Product Characterization Report

for the

SP3243 Family of Products

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Date: Aug 17, 2006

Table of Contents

Introduction: This product family characterization was done as part of the qualification of Sipex's fabrication site transfer from Sipex's Hillview Fab in Milpitas, CA, to a contract foundry, Episil, in Taiwan. This characterization report summarizes data for key SP3243 product family characteristics and contains distributions for all parameters. A complete listing of the product numbers covered by this characterization report is included in the "Conclusion" section of this report.

Wafer Fab: Episil
Fab Location: Taiwan
Process: Episil - 1x - SC2- mah - a
MS: 1105
Assembly location: Carsem

Characterization Procedure:

Episil Lot number(s): C30P44
Hillview Lot number(s): 96890
Temperatures: Ambient (25C), 85C, -40C
Tester: LTX
Test Program: SP3243ECH.AT

Data Summary:

Key Parameter Data Summary Across Temperature

Key Parameter	Units	Hillview Fab Distribution Mean	Hillview Fab Distribution Variance	Hillview Fab Cpk (across temp)		Episil Fab Distribution Mean	Episil Fab Distribution Variance	Episil Fab Cpk (across temp)
3.000: 232 RX VOH -1MA @ 3V Vcc, 85° C	V	2.577	11.449E-03	>4.0000		2.594	5.898E-03	>4.0000
3.005:232 RX VOL 1.6MA @ 3V Vcc, 85° C	mV	267.375	5.472	>4.0000		257.773	5.427	>4.0000
7.000:232 T1 VOH, 3K LOAD @ 3V Vcc, 25° C	V	5.175	44.693E-03	1.3074		5.208	39.081E-03	1.7717
6.000: 232 TX ISC VOH TO GND @ 3V Vcc, 85° C	uA	-0.01175	212.550	>4.0000		-0.01682	959.638	>4.0000
6.003: 232 TX ISC VOL TO GND @ 3V Vcc, 85° C	uA	0.01791	207.095	>4.0000		0.01774	521.131	>4.0000
4.000: 232 RX RIN @ 3V Vcc, -40° C	kΩ	4.474	0.1167	>4.0000		3.099	0.1434	0.2304
4.001: 232 RX RIN @ 3V Vcc, -40° C	kΩ	4.464	0.1178	>4.0000		3.070	0.1393	0.1672
4.002: 232 RX RIN @ 3V Vcc, -40° C	kΩ	4.465	0.1180	>4.0000		3.104	0.1381	0.2513
4.003: 232 RX RIN @ 3V Vcc, -40° C	kΩ	4.462	0.1184	>4.0000		3.116	0.1390	0.2775
4.004: 232 RX RIN @ 3V Vcc, -40° C	kΩ	4.465	0.1139	>4.0000		3.080	0.1359	0.1970
17.004: T1 SKEW @ 3V Vcc, -40° C	ns	427.878	50.234	N/A		483.666	180.067	0.0302
17.006: T2 SKEW @ 3V Vcc, -40° C	ns	435.757	52.083	N/A		466.999	147.465	0.0746
17.008: T3 SKEW @ 3V Vcc, -40° C	ns	407.878	38.223	N/A		443.333	29.046	0.6503

Conclusion:

Characterization data over temperature and Vcc range show datasheet parameters meet the spec. Cpk's for most parameters are comparable between Hillview and Episil although some show a temperature dependence that tends to produce lower Cpk's in this analysis.

The performance of SP3243 parts fabricated at Episil are comparable to the current SP3243 parts built from the Hillview fab.

This characterization report applies to the following SP3243 family of product part numbers:

SP3243CR
SP3243CR-L
SP3243BCA
SP3243BCA-L
SP3243BCR
SP3243BCR-L
SP3243BCT
SP3243BCT-L
SP3243BCY
SP3243BCY-L
SP3243BEA
SP3243BEA-L
SP3243BER
SP3243BER-L
SP3243BET
SP3243BET-L
SP3243BEY
SP3243BEY-L
SP3243CA
SP3243CA-L
SP3243CT
SP3243CT-L
SP3243CY
SP3243CY-L
SP3243EA
SP3243EA-L
SP3243EBCA
SP3243EBCA-L
SP3243EBCR
SP3243EBCR-L
SP3243EBCT
SP3243EBCT-L
SP3243EBCY
SP3243EBCY-L
SP3243EBEA
SP3243EBEA-L
SP3243EBER
SP3243EBER-L
SP3243EBET
SP3243EBET-L
SP3243EBEY
SP3243EBEY-L
SP3243ECA
SP3243ECA-L
SP3243ECR
SP3243ECR-L
SP3243ECT
SP3243ECT-L
SP3243ECY
SP3243ECY-L
SP3243EEA
SP3243EEA-L
SP3243EER
SP3243EER-L
SP3243EET
SP3243EET-L
SP3243EEY
SP3243EEY-L
SP3243ER
SP3243ER-L
SP3243ET
SP3243ET-L
SP3243EY
SP3243EY-L
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SP3243EHET-L
SP3243EHEY
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SP3243EHCA
SP3243EHCA-L
SP3243EHCR
SP3243EHCR-L
SP3243EHCT
SP3243EHCT-L
SP3243EHCY
SP3243EHCY-L
SP3243EHEA-L
SP3243EHER
SP3243EHER-L
SP3243EUCA
SP3243EUCA-L
SP3243EUCR
SP3243EUCR-L
SP3243EUCT
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SP3243EUCY-L
SP3243EUEA
SP3243EUEA-L
SP3243EUER
SP3243EUER-L
SP3243EUET
SP3243EUET-L
SP3243EUEY
SP3243EUEY-L
SP3243HCA
SP3243HCA-L
SP3243HCT-L
SP3243HEA
SP3243HEA-L
SP3243HET-L
SP3243UCA
SP3243UCA-L
SP3243UCR
SP3243UCR-L
SP3243UCT
SP3243UCT-L
SP3243UCY
SP3243UCY-L
SP3243UEA
SP3243UEA-L
SP3243UER
SP3243UER-L
SP3243UET
SP3243UET-L
SP3243UEY
SP3243UEY-L

Appendix A
Characterization Data Histograms

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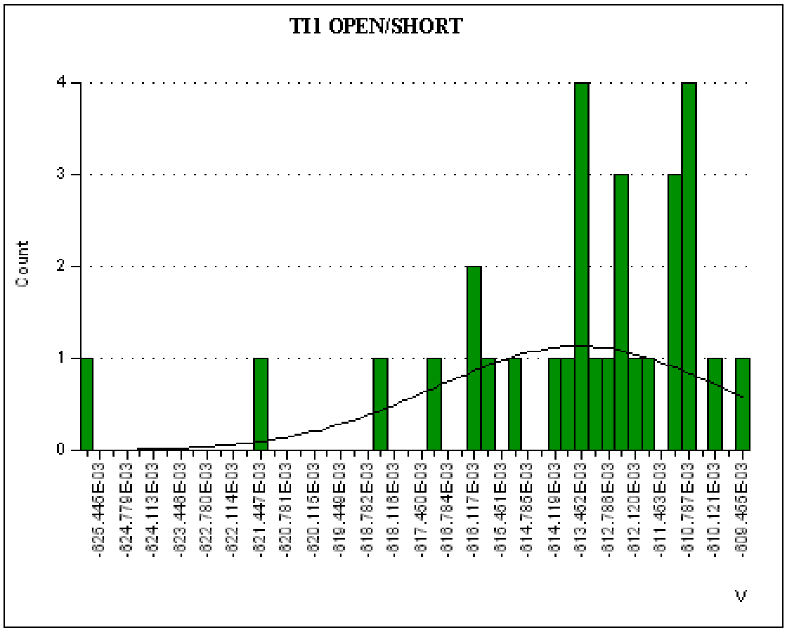
Thu 30 Mar 2006, 11:32 AM

Test.Number=1.000, Test.Name=TI1 OPEN/SHORT



Statistics: (V)

Min	-625.778E-03	**Skew**	-1.8173
Max	-609.455E-03	**StatHigh**	N/A
Mean	-613.651E-03	**StatLow**	N/A
StdDev	3.527E-03	**NWithinSpec**	N/A
25%	-615.019E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-603.070E-03	**90%**	-610.708E-03
		Range	16.324E-03
Mean-3*StdDev	-624.231E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

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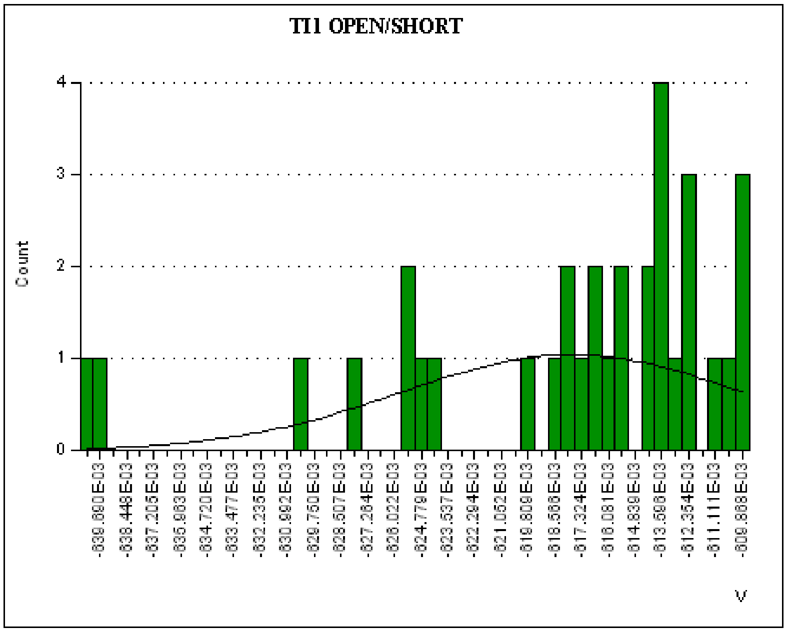


Statistics: (V)

Min	-640.312E-03	**StatLow**	N/A
Max	-609.868E-03	**NWithinSpec**	N/A
Mean	-617.998E-03	**NOutsideSpec**	N/A
StdDev	7.843E-03	**90%**	-610.737E-03
25%	-619.635E-03	**Range**	30.443E-03
Mean+3*StdDev	-594.468E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-641.527E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.5091		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

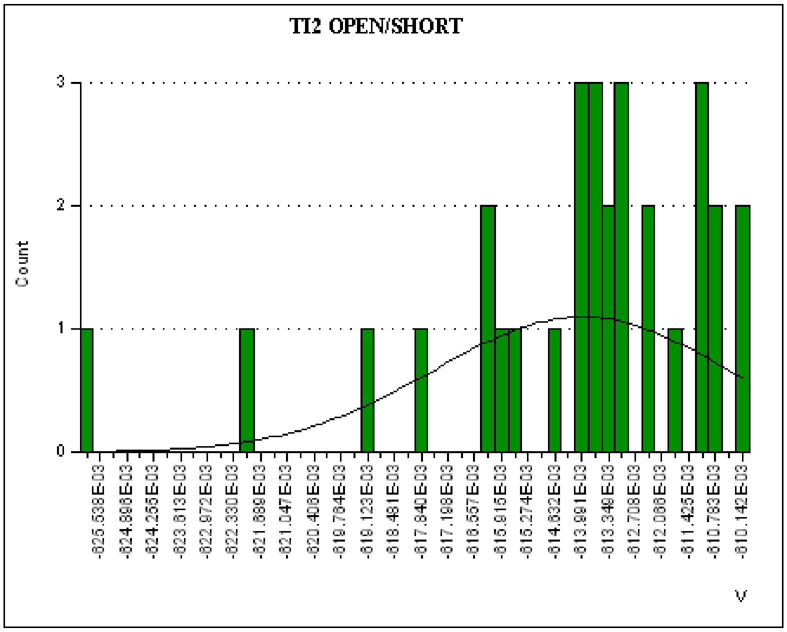
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=1.001, Test.Name=TI2 OPEN/SHORT



Statistics: (V)

Min	-625.859E-03	**Skew**	-1.7436
Max	-610.142E-03	**StatHigh**	N/A
Mean	-614.117E-03	**StatLow**	N/A
StdDev	3.495E-03	**NWithinSpec**	N/A
25%	-615.706E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-603.630E-03	**90%**	-610.790E-03
		Range	15.717E-03
Mean-3*StdDev	-624.603E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

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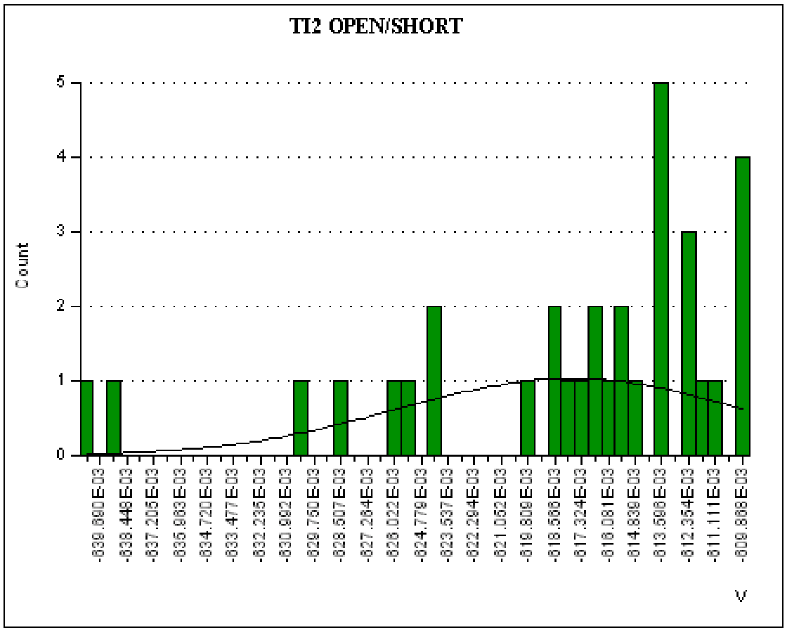


Statistics: (V)

Min	-640.312E-03	**StatLow**	N/A
Max	-609.868E-03	**NWithinSpec**	N/A
Mean	-617.990E-03	**NOutsideSpec**	N/A
StdDev	7.908E-03	**90%**	-610.131E-03
25%	-619.711E-03	**Range**	30.443E-03
Mean+3*StdDev	-594.265E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-641.714E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.4709		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

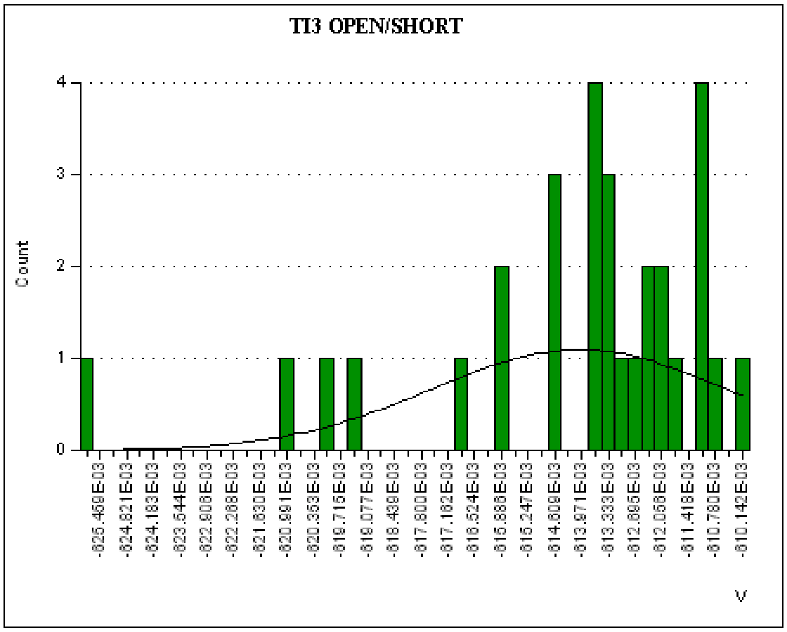
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=1.002, Test.Name=TI3 OPEN/SHORT



Statistics: (V)

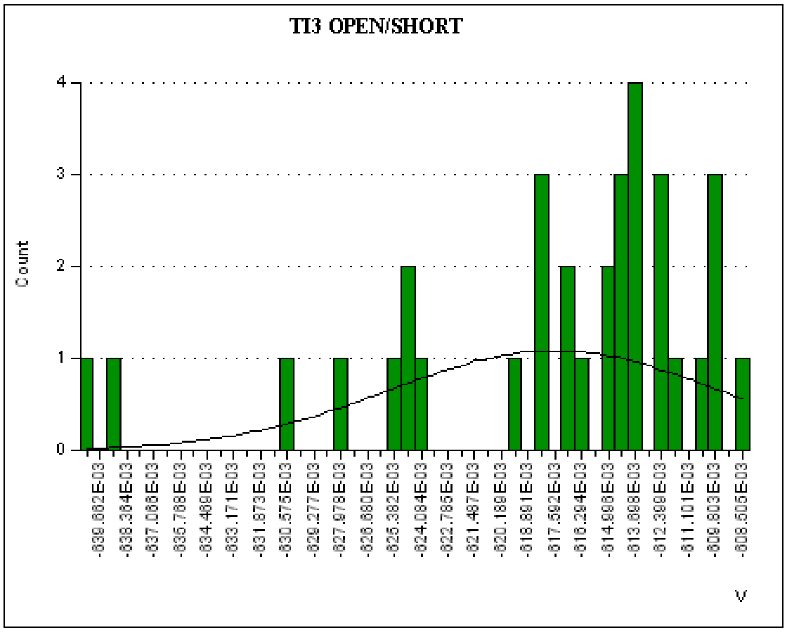
Min	-625.778E-03	**Skew**	-1.7113
Max	-610.142E-03	**StatHigh**	N/A
Mean	-614.152E-03	**StatLow**	N/A
StdDev	3.487E-03	**NWithinSpec**	N/A
25%	-614.637E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-603.690E-03	**90%**	-610.973E-03
		Range	15.637E-03
Mean-3*StdDev	-624.615E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=1.002, Test.Name=TI3 OPEN/SHORT



Statistics: (V)

Min	-640.312E-03	**StatLow**	N/A
Max	-608.505E-03	**NWithinSpec**	N/A
Mean	-617.855E-03	**NOutsideSpec**	N/A
StdDev	7.878E-03	**90%**	-609.944E-03
25%	-619.635E-03	**Range**	31.807E-03
Mean+3*StdDev	-594.222E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-641.489E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-1.4755		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

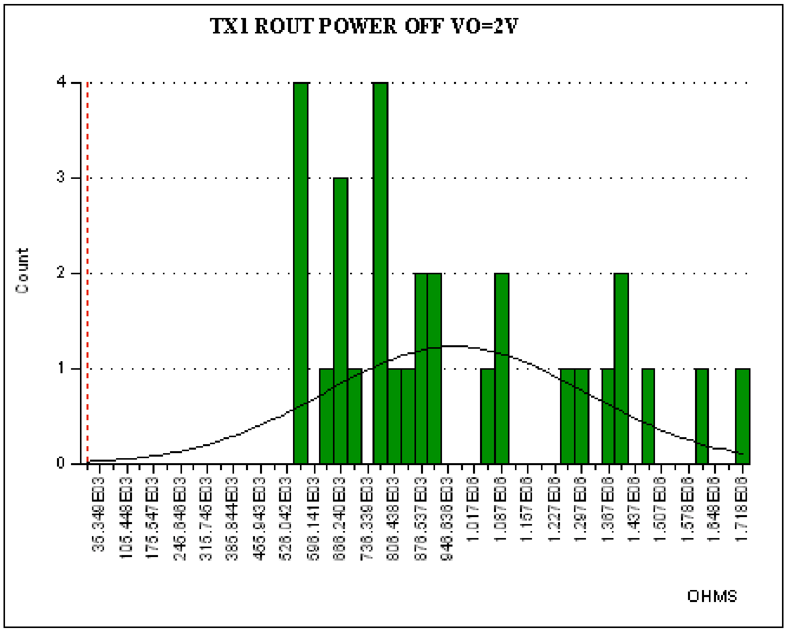
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=2.000, Test.Name=TX1 ROUT POWER OFF VO=2V



Statistics: (OHMS)

Min	553.279E03	**Skew**	0.7154
Max	1.718E06	**StatHigh**	N/A
Mean	955.750E03	**StatLow**	N/A
StdDev	340.385E03	**NWithinSpec**	30
25%	676.950E03	**NOutsideSpec**	0
Mean+3*StdDev	1.977E06	**90%**	1.444E06
		Range	1.164E06
Mean-3*StdDev	-65.405E03	**NOutsideSpec**	0
Cpk	0.9357		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

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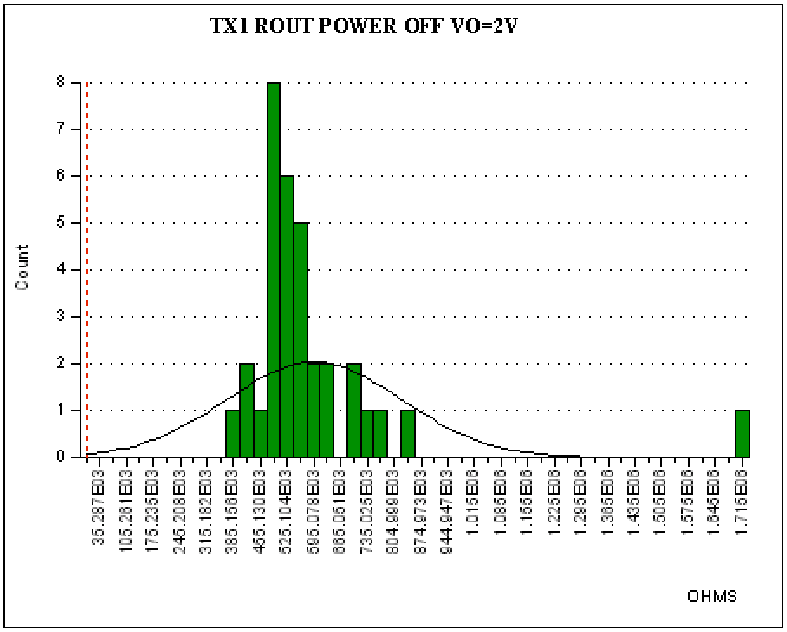


Statistics: (OHMS)

Min	382.114E03	**StatLow**	N/A
Max	1.715E06	**NWithinSpec**	33
Mean	590.385E03	**NOutsideSpec**	0
StdDev	226.548E03	**90%**	717.556E03
25%	487.877E03	**Range**	1.333E06
Mean+3*StdDev	1.270E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-89.258E03	**Cpl**	0.8682
		Cpu	N/A
Cpk	0.8682		
Skew	4.0536		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

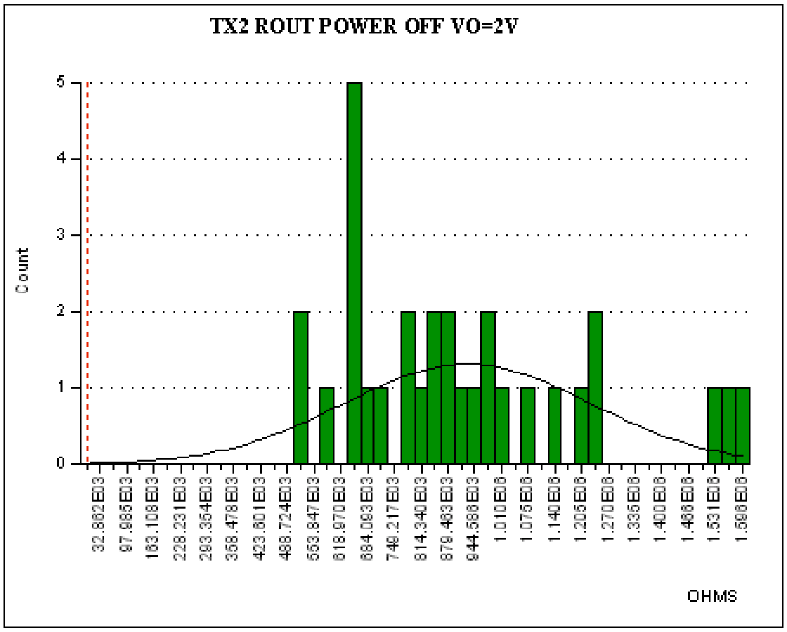
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=2.001, Test.Name=TX2 ROUT POWER OFF VO=2V



Statistics: (OHMS)

Min	515.261E03	**Skew**	0.8781
Max	1.596E06	**StatHigh**	N/A
Mean	917.128E03	**StatLow**	N/A
StdDev	297.177E03	**NWithinSpec**	30
25%	662.706E03	**NOutsideSpec**	0
Mean+3*StdDev	1.809E06	**90%**	1.389E06
		Range	1.081E06
Mean-3*StdDev	25.596E03	**NOutsideSpec**	0
Cpk	1.0284		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

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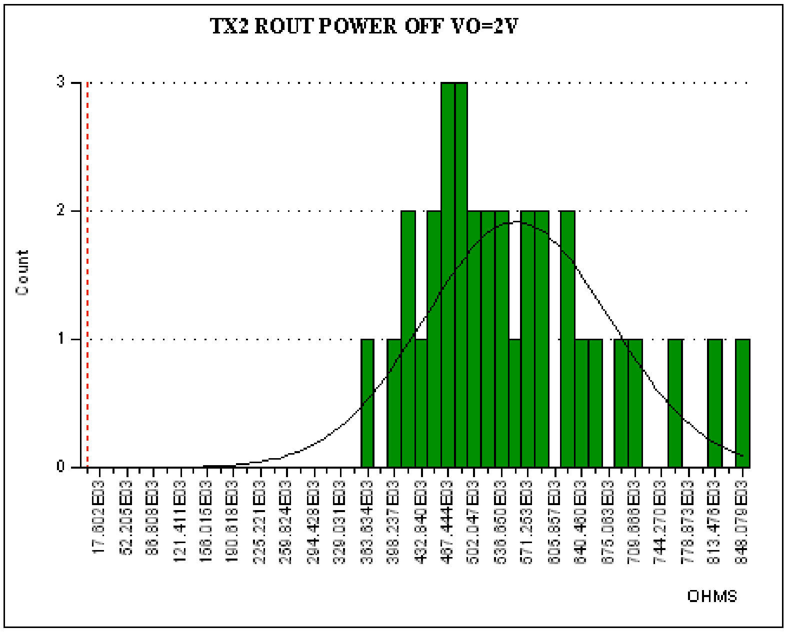


Statistics: (OHMS)

Min	364.540E03	**StatLow**	N/A
Max	848.079E03	**NWithinSpec**	33
Mean	549.738E03	**NOutsideSpec**	0
StdDev	118.944E03	**90%**	711.119E03
25%	467.725E03	**Range**	483.540E03
Mean+3*StdDev	906.570E03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	192.906E03	**Cpl**	1.5398
		Cpu	N/A
Cpk	1.5398		
Skew	0.8627		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

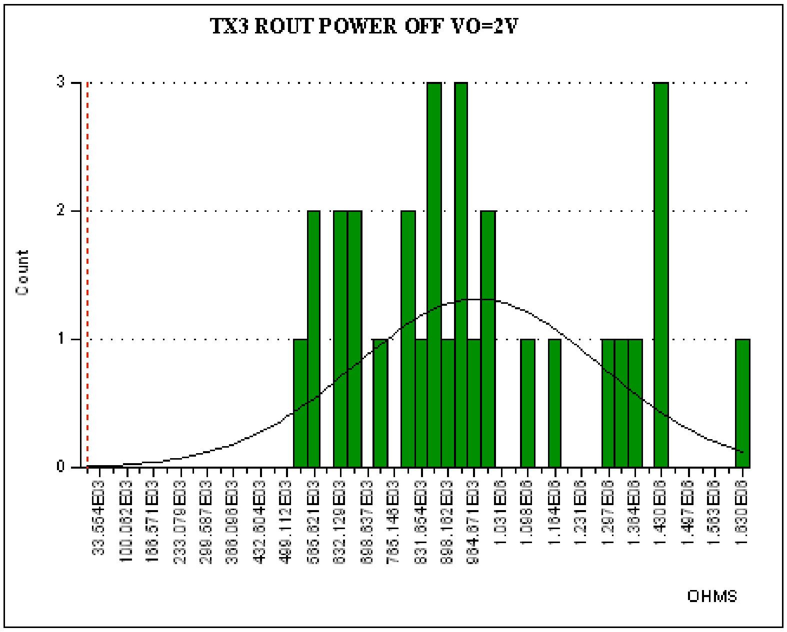
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=2.002, Test.Name=TX3 ROUT POWER OFF VO=2V



Statistics: (OHMS)

Min	534.496E03	**Skew**	0.5557
Max	1.630E06	**StatHigh**	N/A
Mean	960.714E03	**StatLow**	N/A
StdDev	302.275E03	**NWithinSpec**	30
25%	733.719E03	**NOutsideSpec**	0
Mean+3*StdDev	1.868E06	**90%**	1.424E06
		Range	1.095E06
Mean-3*StdDev	53.890E03	**NOutsideSpec**	0
Cpk	1.0591		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

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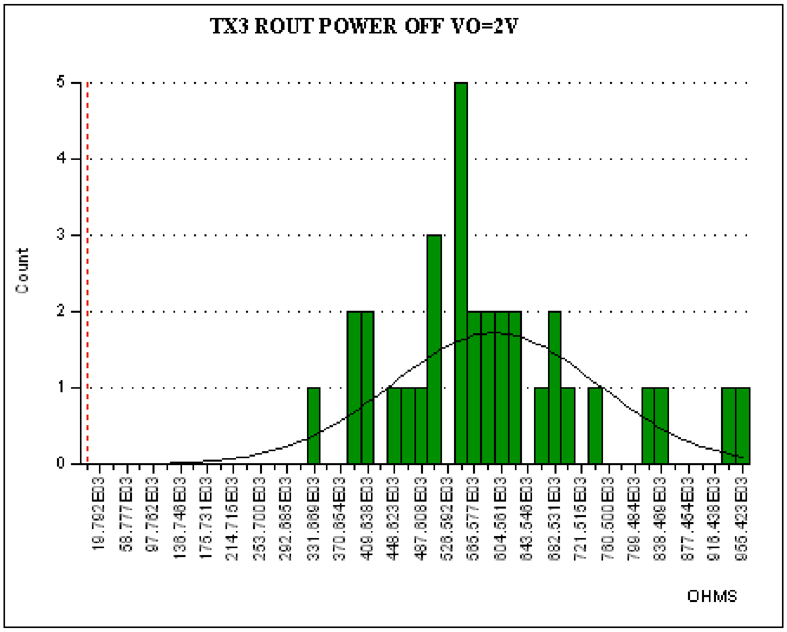

Statistics: (OHMS)

Min	327.307E03	**StatLow**	N/A
Max	955.423E03	**NWithinSpec**	33
Mean	588.354E03	**NOutsideSpec**	0
StdDev	149.381E03	**90%**	821.705E03
25%	511.489E03	**Range**	628.116E03
Mean+3*StdDev	1.036E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	140.211E03	**Cpl**	1.3122
		Cpu	N/A
Cpk	1.3122		
Skew	0.7753		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

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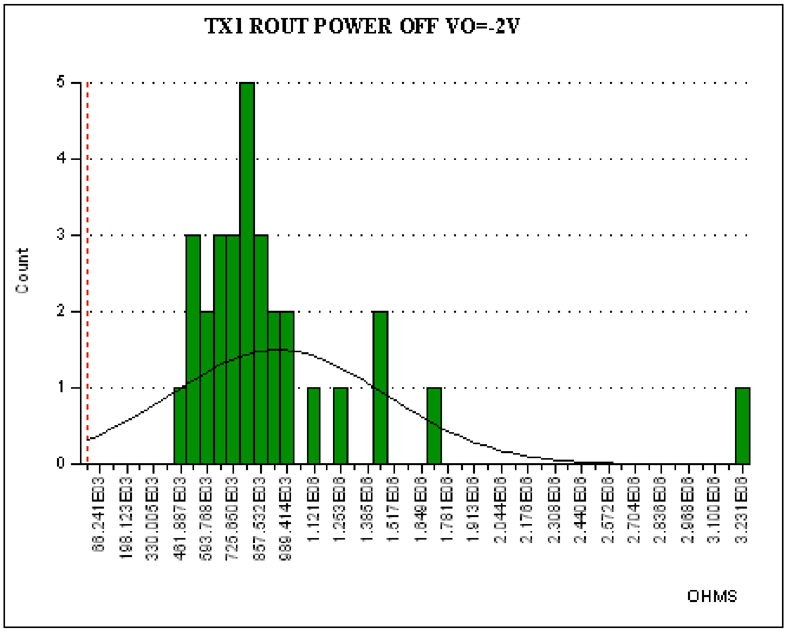

Statistics: (OHMS)

Min	434.270E03	**Skew**	3.1278
Max	3.231E06	**StatHigh**	N/A
Mean	933.808E03	**StatLow**	N/A
StdDev	527.474E03	**NWithinSpec**	30
25%	668.335E03	**NOutsideSpec**	0
Mean+3*StdDev	2.516E06	**90%**	1.463E06
		Range	2.797E06
Mean-3*StdDev	-648.613E03	**NOutsideSpec**	0
Cpk	0.5899		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

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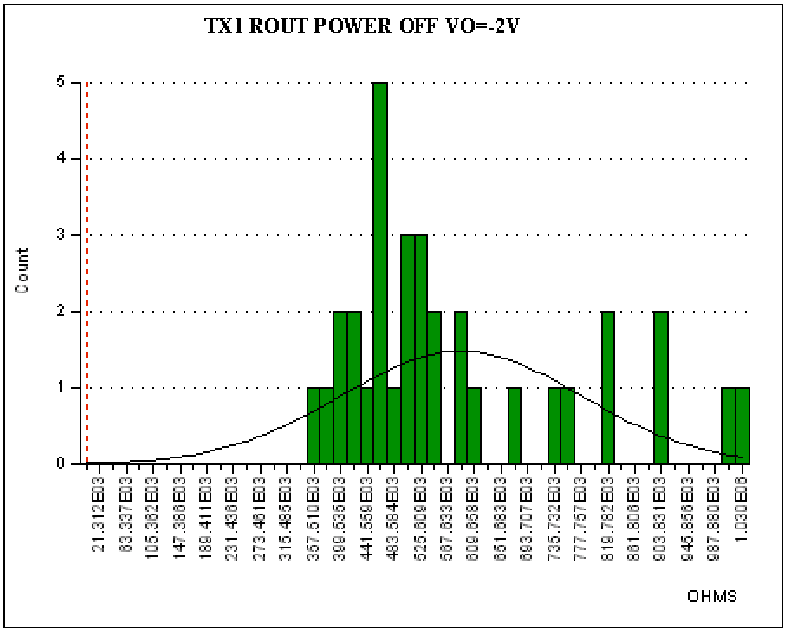


Statistics: (OHMS)

Min	364.540E03	**StatLow**	N/A
Max	1.030E06	**NWithinSpec**	33
Mean	582.788E03	**NOutsideSpec**	0
StdDev	186.664E03	**90%**	906.264E03
25%	458.258E03	**Range**	665.365E03
Mean+3*StdDev	1.143E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	22.797E03	**Cpl**	1.0402
Cpk	1.0402	**Cpu**	N/A
Skew	1.1069		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

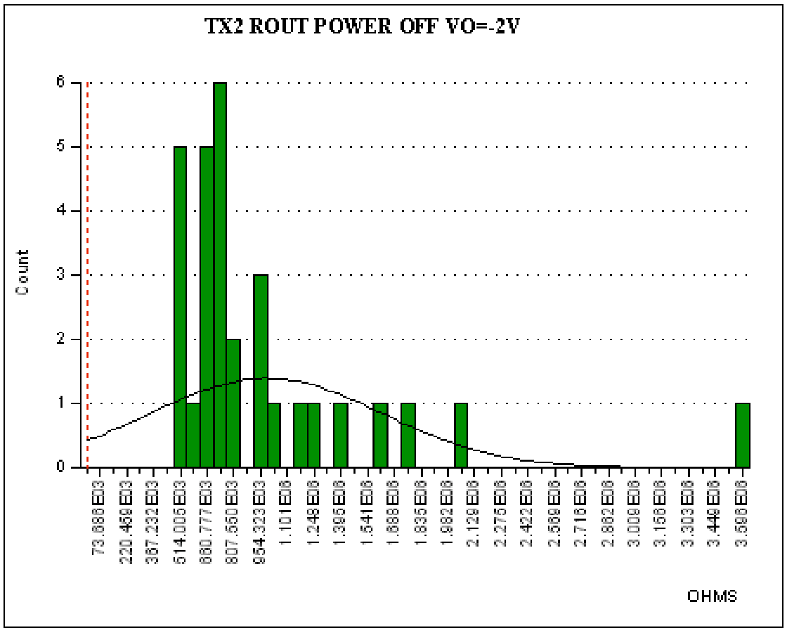
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=2.004, Test.Name=TX2 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

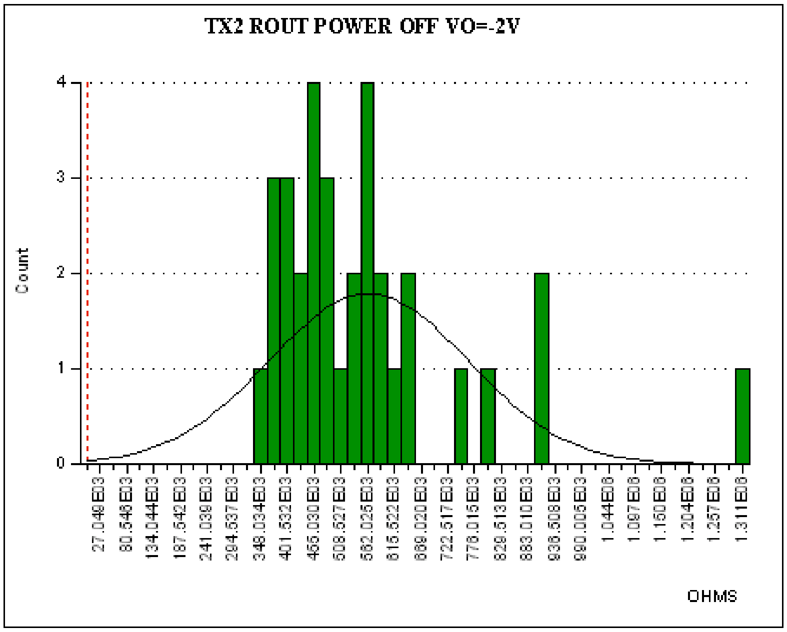
Min	488.103E03	**Skew**	2.8532
Max	3.596E06	**StatHigh**	N/A
Mean	975.650E03	**StatLow**	N/A
StdDev	630.795E03	**NWithinSpec**	30
25%	657.183E03	**NOutsideSpec**	0
Mean+3*StdDev	2.868E06	**90%**	1.705E06
		Range	3.108E06
Mean-3*StdDev	-916.736E03	**NOutsideSpec**	0
Cpk	0.5154		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.004, Test.Name=TX2 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

Min	356.344E03	**StatLow**	N/A
Max	1.311E06	**NWithinSpec**	33
Mean	557.372E03	**NOutsideSpec**	0
StdDev	197.079E03	**90%**	809.120E03
25%	425.081E03	**Range**	954.647E03
Mean+3*StdDev	1.149E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-33.865E03	**Cpl**	0.9422
		Cpu	N/A
Cpk	0.9422		
Skew	2.1270		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

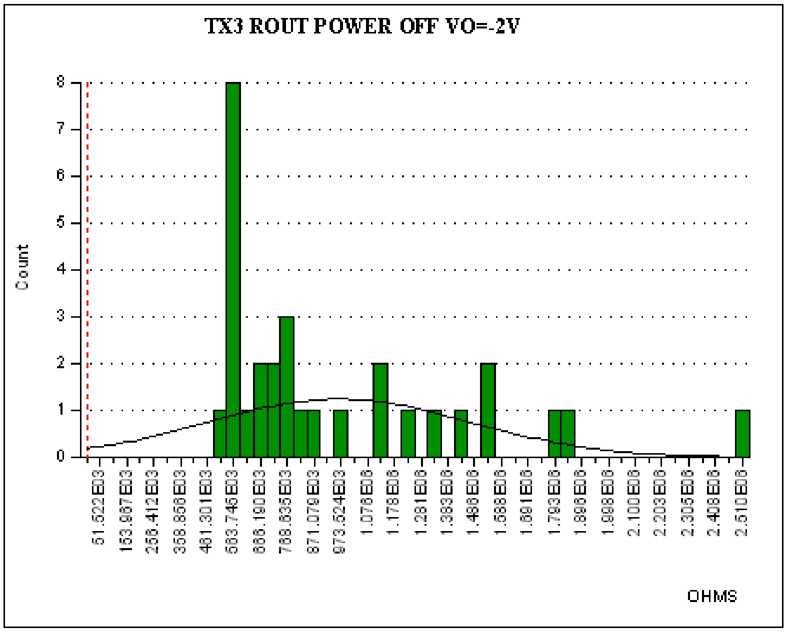
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=2.005, Test.Name=TX3 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

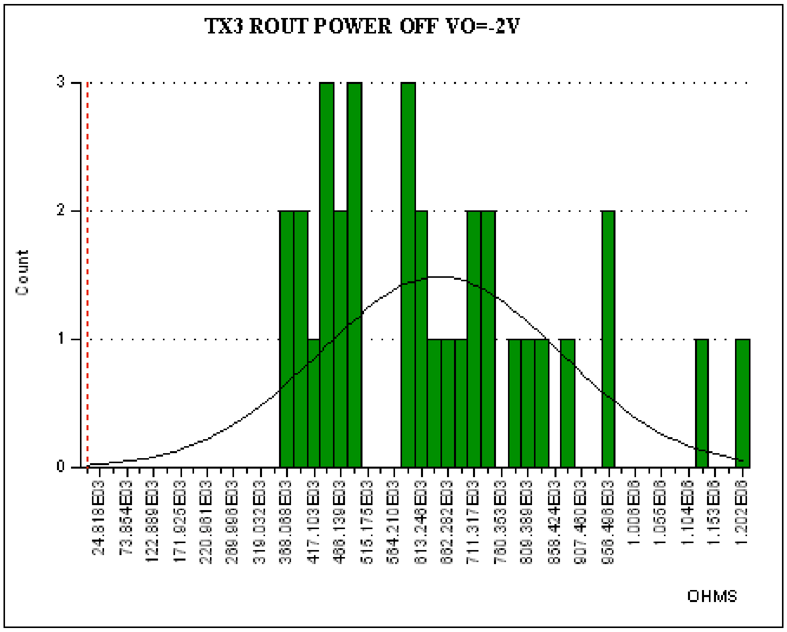
Min	522.094E03	**Skew**	1.4885
Max	2.510E06	**StatHigh**	N/A
Mean	959.510E03	**StatLow**	N/A
StdDev	492.341E03	**NWithinSpec**	30
25%	577.622E03	**NOutsideSpec**	0
Mean+3*StdDev	2.437E06	**90%**	1.648E06
		Range	1.988E06
Mean-3*StdDev	-517.511E03	**NOutsideSpec**	0
Cpk	0.6494		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.005, Test.Name=TX3 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

Min	360.395E03	**StatLow**	N/A
Max	1.202E06	**NWithinSpec**	33
Mean	639.932E03	**NOutsideSpec**	0
StdDev	216.986E03	**90%**	949.695E03
25%	469.108E03	**Range**	841.279E03
Mean+3*StdDev	1.291E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-11.025E03	**Cpl**	0.9826
		Cpu	N/A
Cpk	0.9826		
Skew	0.8536		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

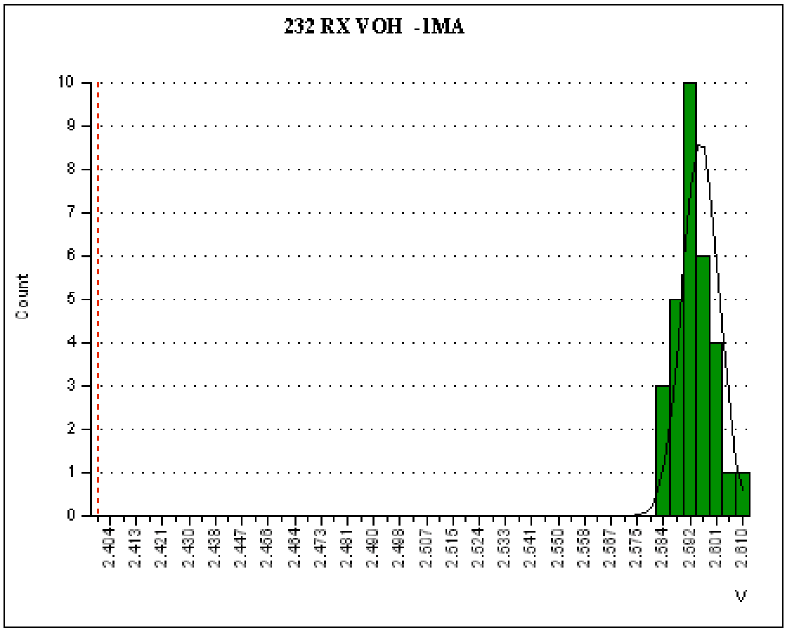
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.000, Test.Name=232 RX VOH -1MA



Statistics: (V)

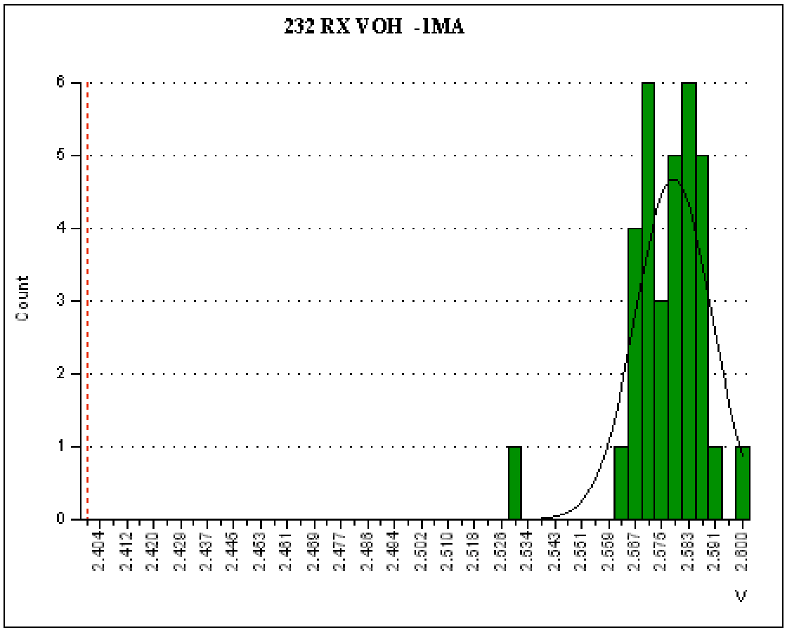
Min	2.583	**Skew**	0.4968
Max	2.610	**StatHigh**	N/A
Mean	2.594	**StatLow**	N/A
StdDev	5.898E-03	**NWithinSpec**	30
25%	2.589	**NOutsideSpec**	0
Mean+3*StdDev	2.612	**90%**	2.601
		Range	26.310E-03
Mean-3*StdDev	2.576	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.000, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.532	**StatLow**	N/A
Max	2.600	**NWithinSpec**	33
Mean	2.577	**NOutsideSpec**	0
StdDev	11.449E-03	**90%**	2.586
25%	2.570	**Range**	67.760E-03
Mean+3*StdDev	2.611	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.542	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-1.6842		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

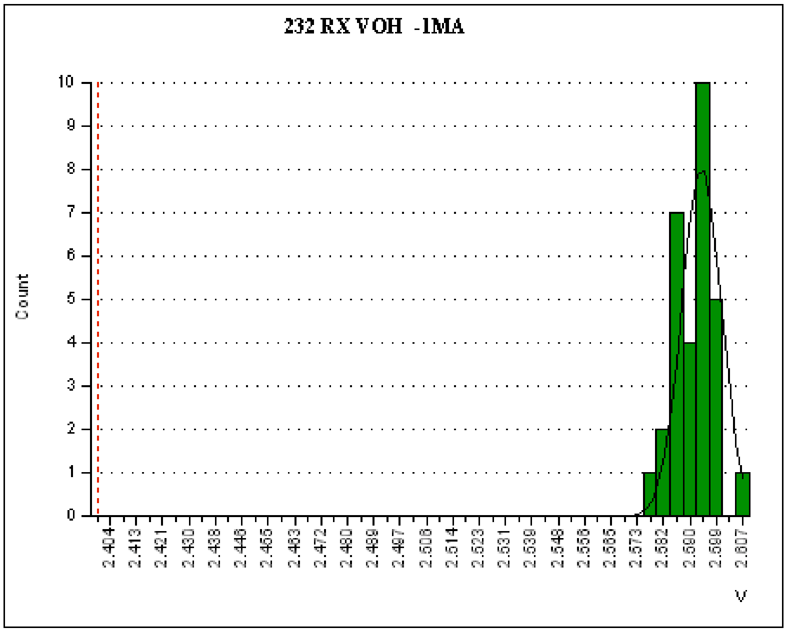
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.001, Test.Name=232 RX VOH -1MA



Statistics: (V)

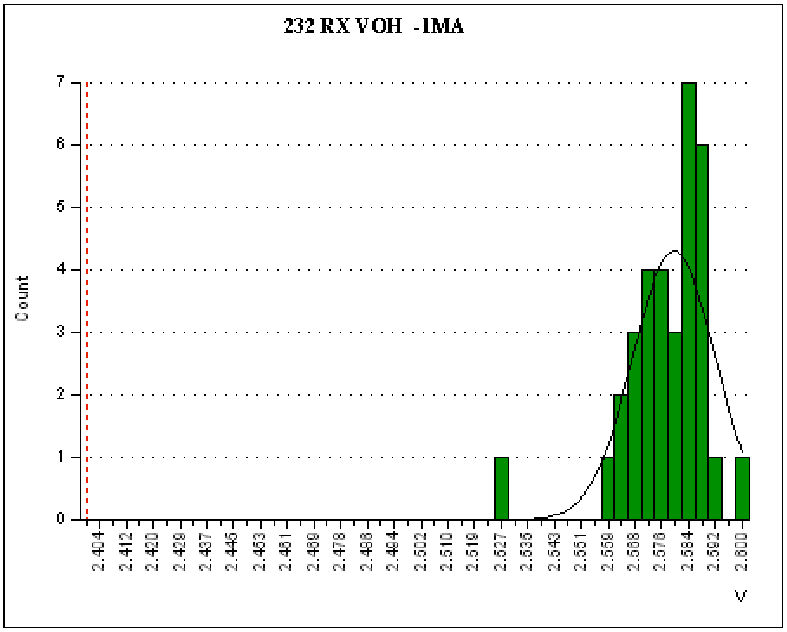
Min	2.577	**Skew**	-0.0676
Max	2.607	**StatHigh**	N/A
Mean	2.592	**StatLow**	N/A
StdDev	6.293E-03	**NWithinSpec**	30
25%	2.587	**NOutsideSpec**	0
Mean+3*StdDev	2.611	**90%**	2.599
		Range	29.881E-03
Mean-3*StdDev	2.573	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.001, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.528	**StatLow**	N/A
Max	2.600	**NWithinSpec**	33
Mean	2.577	**NOutsideSpec**	0
StdDev	12.497E-03	**90%**	2.588
25%	2.572	**Range**	71.819E-03
Mean+3*StdDev	2.615	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.540	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-1.8151		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

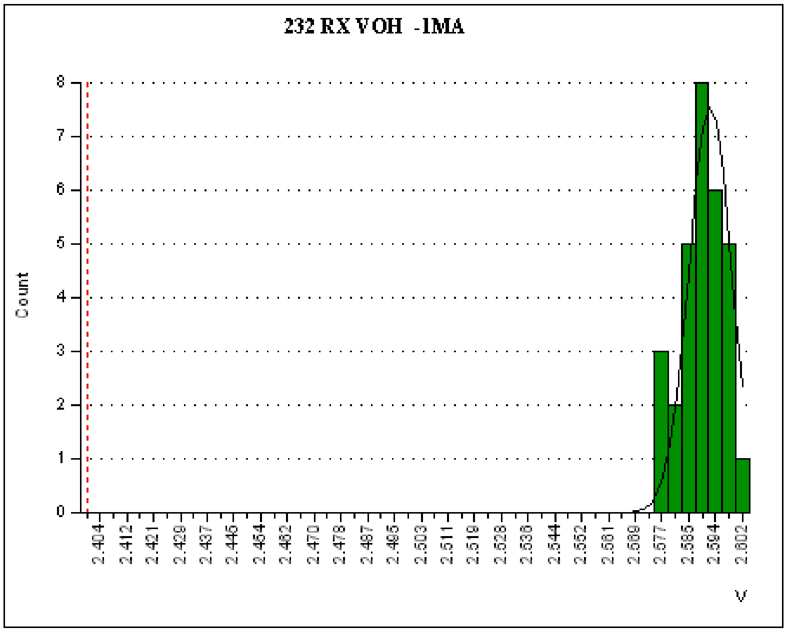
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.002, Test.Name=232 RX VOH -1MA



Statistics: (V)

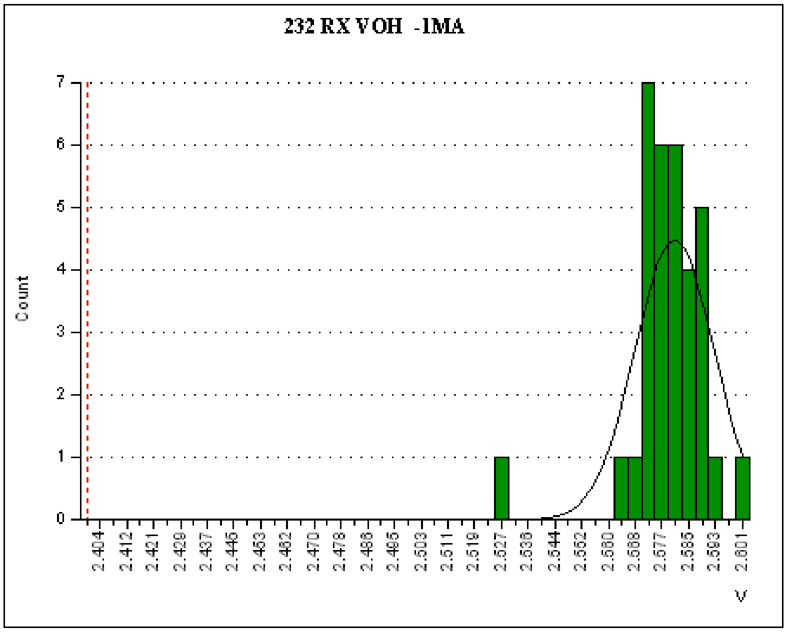
Min	2.578	**Skew**	-0.2126
Max	2.602	**StatHigh**	N/A
Mean	2.590	**StatLow**	N/A
StdDev	6.529E-03	**NWithinSpec**	30
25%	2.586	**NOutsideSpec**	0
Mean+3*StdDev	2.610	**90%**	2.599
		Range	23.921E-03
Mean-3*StdDev	2.570	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.002, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.527	**StatLow**	N/A
Max	2.601	**NWithinSpec**	33
Mean	2.579	**NOutsideSpec**	0
StdDev	12.090E-03	**90%**	2.588
25%	2.573	**Range**	74.760E-03
Mean+3*StdDev	2.615	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.542	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-2.3429		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

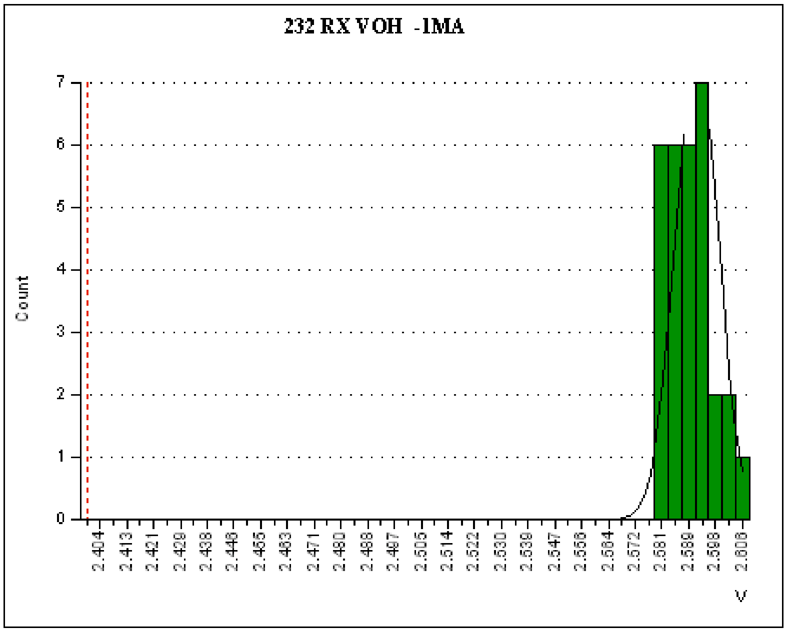
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.003, Test.Name=232 RX VOH -1MA



Statistics: (V)

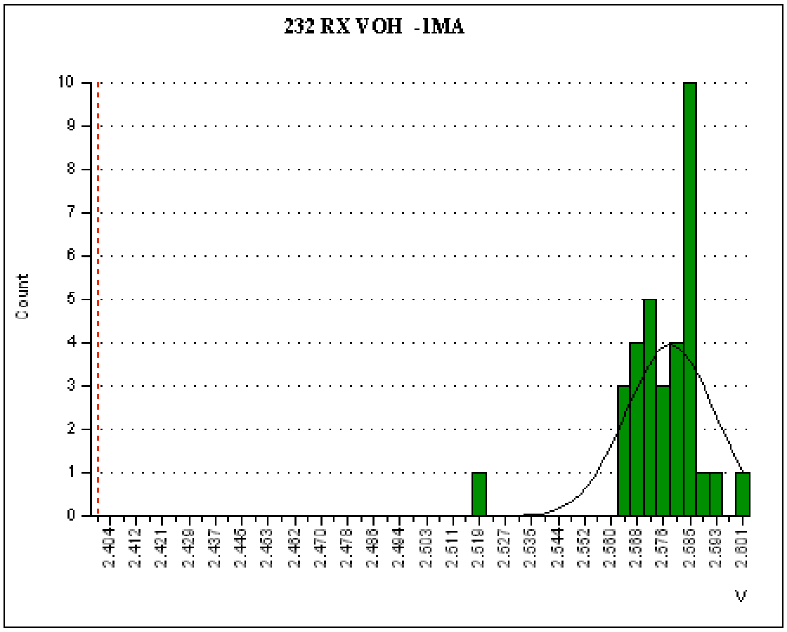
Min	2.580	**Skew**	0.4526
Max	2.606	**StatHigh**	N/A
Mean	2.590	**StatLow**	N/A
StdDev	6.716E-03	**NWithinSpec**	30
25%	2.584	**NOutsideSpec**	0
Mean+3*StdDev	2.610	**90%**	2.600
		Range	26.451E-03
Mean-3*StdDev	2.570	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.003, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.518	**StatLow**	N/A
Max	2.601	**NWithinSpec**	33
Mean	2.577	**NOutsideSpec**	0
StdDev	13.680E-03	**90%**	2.587
25%	2.570	**Range**	83.307E-03
Mean+3*StdDev	2.618	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.536	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-2.4214		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

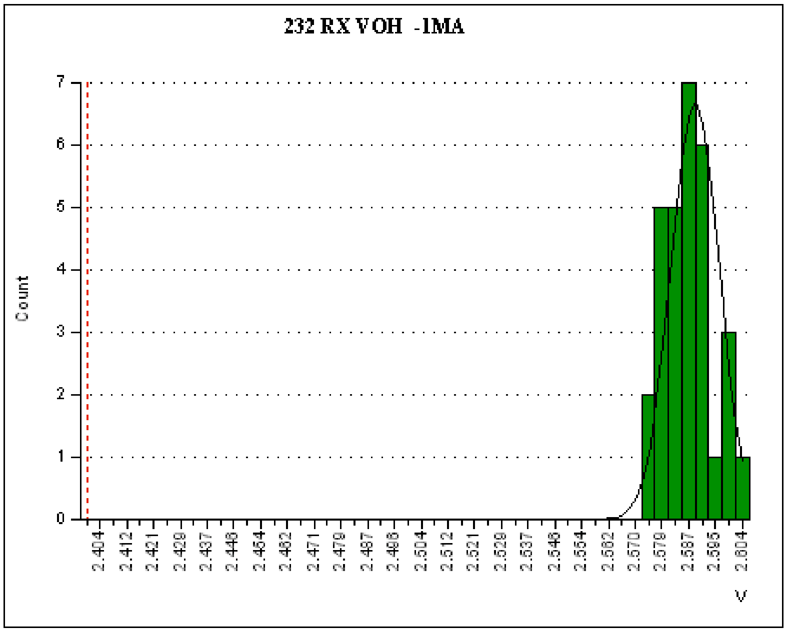
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.004, Test.Name=232 RX VOH -1MA



Statistics: (V)

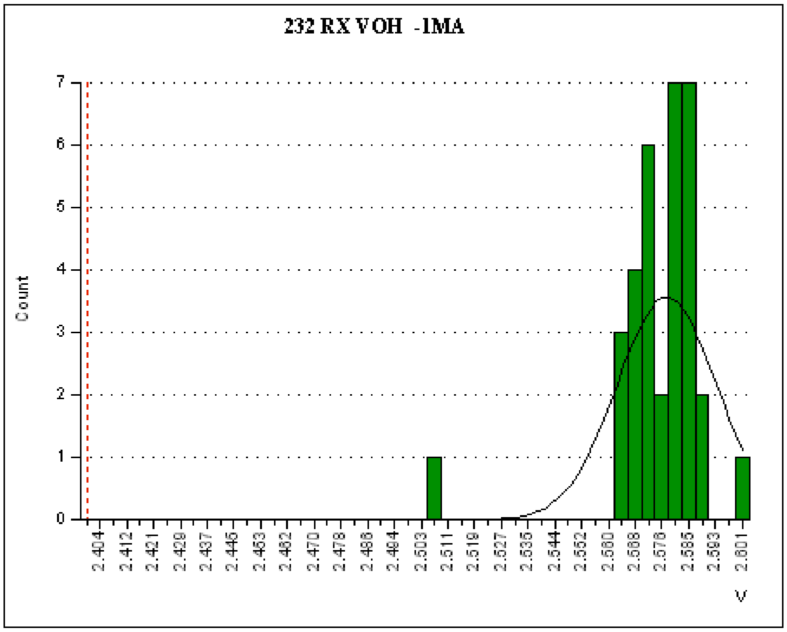
Min	2.575	**Skew**	0.4710
Max	2.604	**StatHigh**	N/A
Mean	2.587	**StatLow**	N/A
StdDev	7.410E-03	**NWithinSpec**	30
25%	2.581	**NOutsideSpec**	0
Mean+3*StdDev	2.609	**90%**	2.599
		Range	29.132E-03
Mean-3*StdDev	2.565	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.004, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.506	**StatLow**	N/A
Max	2.601	**NWithinSpec**	33
Mean	2.576	**NOutsideSpec**	0
StdDev	15.155E-03	**90%**	2.587
25%	2.571	**Range**	94.939E-03
Mean+3*StdDev	2.621	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.530	**Cpl**	3.8681
		Cpu	N/A
Cpk	3.8681		
Skew	-3.0541		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

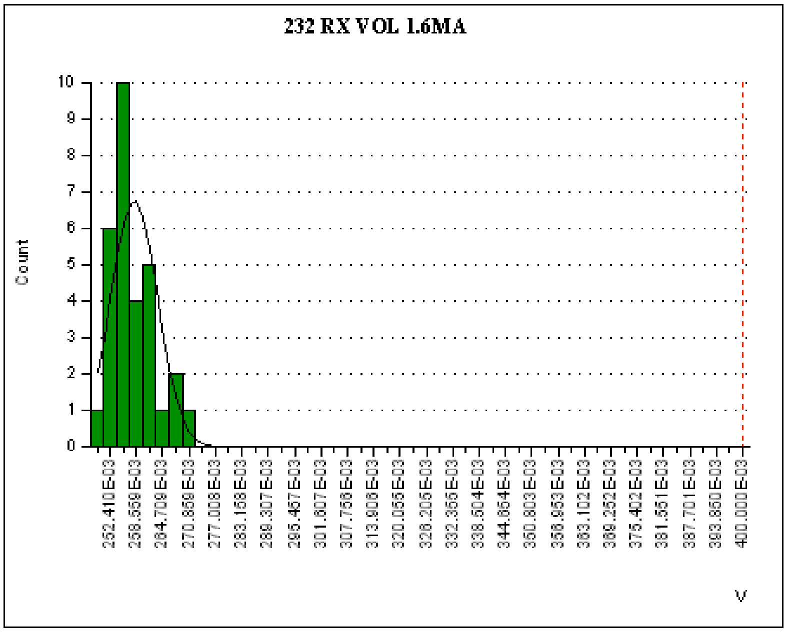
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.005, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

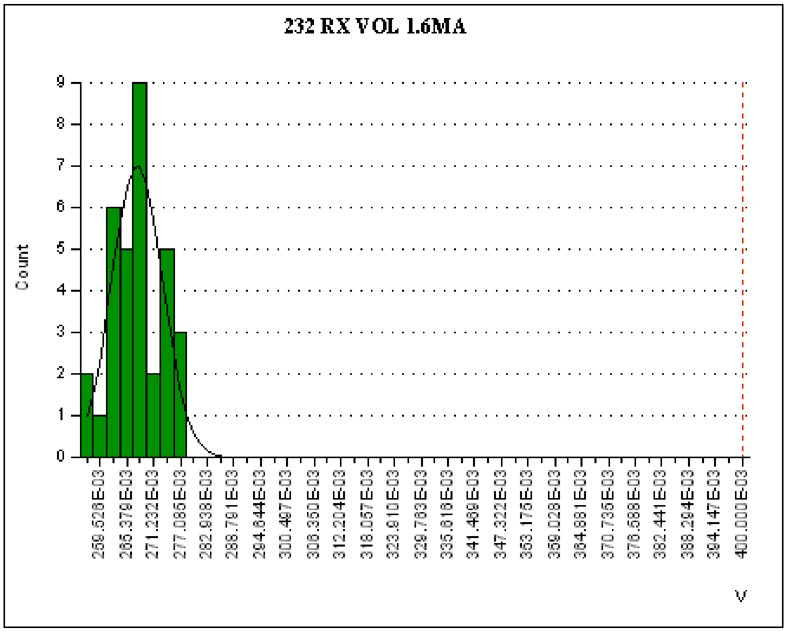
Min	249.335E-03	**Skew**	0.8414
Max	271.325E-03	**StatHigh**	N/A
Mean	257.773E-03	**StatLow**	N/A
StdDev	5.427E-03	**NWithinSpec**	30
25%	254.250E-03	**NOutsideSpec**	0
Mean+3*StdDev	274.055E-03	**90%**	266.441E-03
		Range	21.990E-03
Mean-3*StdDev	241.491E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.005, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	256.599E-03	**StatLow**	N/A
Max	276.569E-03	**NWithinSpec**	33
Mean	267.375E-03	**NOutsideSpec**	0
StdDev	5.472E-03	**90%**	274.410E-03
25%	263.781E-03	**Range**	19.970E-03
Mean+3*StdDev	283.791E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	250.959E-03	**Cpl**	N/A
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.0564		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

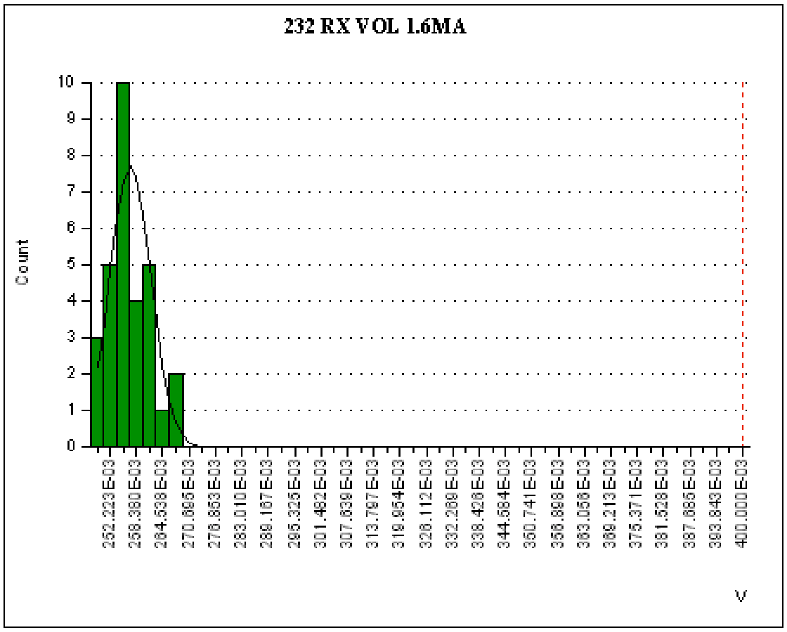
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.006, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

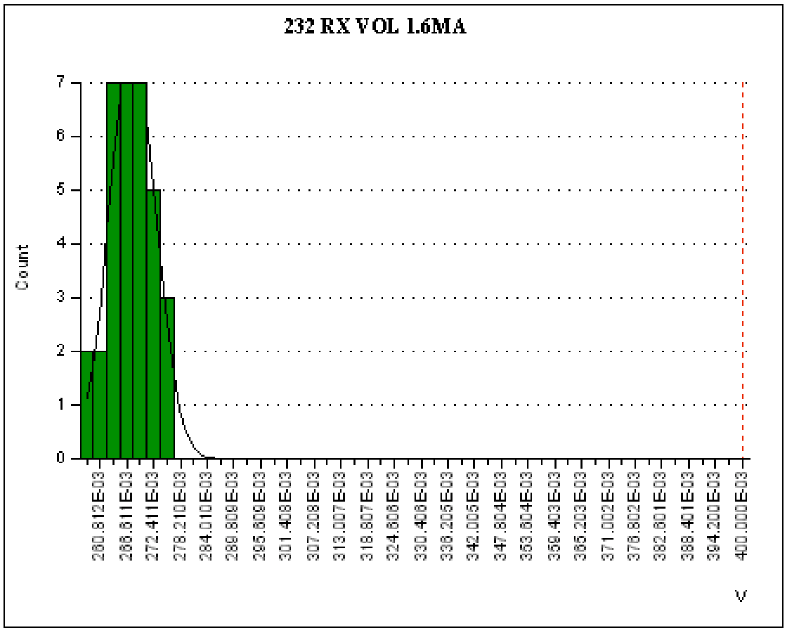
Min	249.144E-03	**Skew**	0.5955
Max	268.111E-03	**StatHigh**	N/A
Mean	256.721E-03	**StatLow**	N/A
StdDev	4.762E-03	**NWithinSpec**	30
25%	252.930E-03	**NOutsideSpec**	0
Mean+3*StdDev	271.006E-03	**90%**	263.189E-03
		Range	18.967E-03
Mean-3*StdDev	242.436E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.006, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	257.912E-03	**StatLow**	N/A
Max	275.913E-03	**NWithinSpec**	33
Mean	267.590E-03	**NOutsideSpec**	0
StdDev	4.951E-03	**90%**	273.829E-03
25%	264.185E-03	**Range**	18.000E-03
Mean+3*StdDev	282.444E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	252.736E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.0643		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

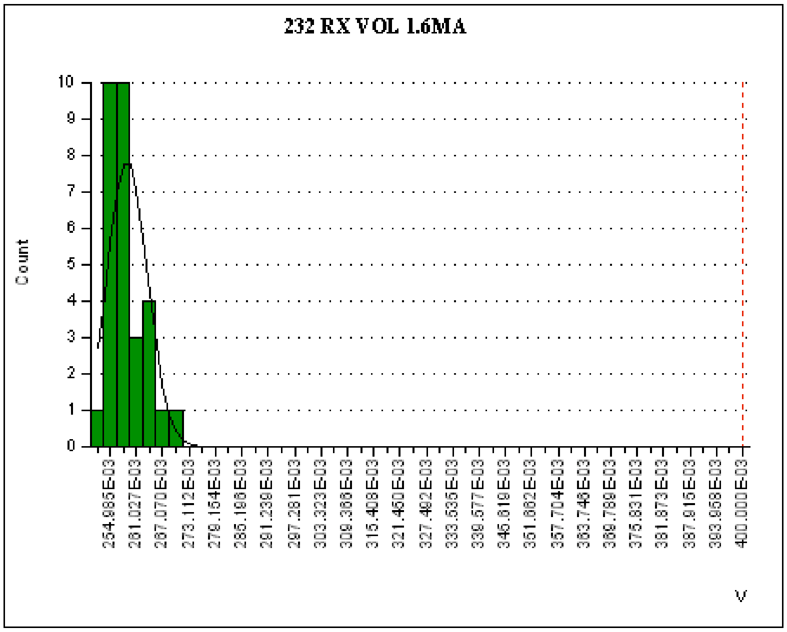
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.007, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

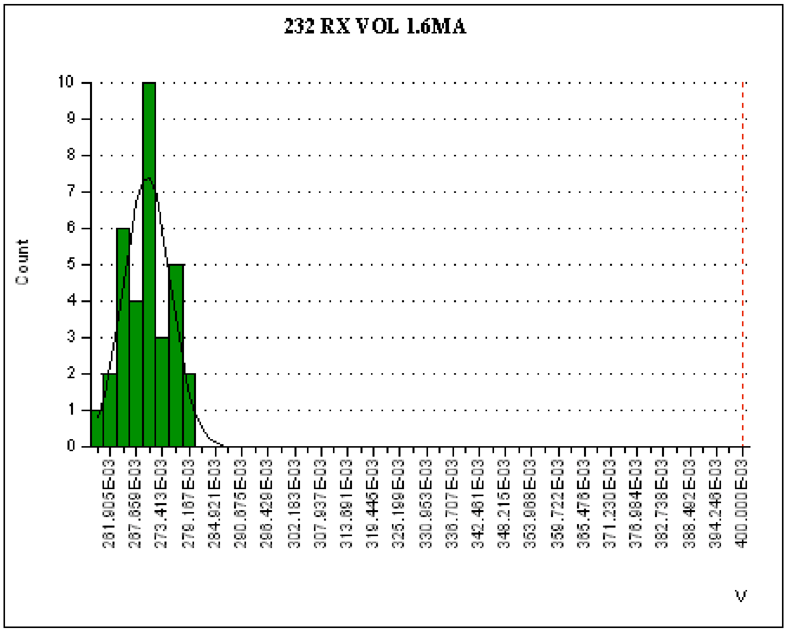
Min	251.964E-03	**Skew**	1.0582
Max	271.465E-03	**StatHigh**	N/A
Mean	258.672E-03	**StatLow**	N/A
StdDev	4.604E-03	**NWithinSpec**	30
25%	255.622E-03	**NOutsideSpec**	0
Mean+3*StdDev	272.486E-03	**90%**	265.298E-03
		Range	19.501E-03
Mean-3*StdDev	244.859E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.007, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	259.028E-03	**StatLow**	N/A
Max	279.276E-03	**NWithinSpec**	33
Mean	269.751E-03	**NOutsideSpec**	0
StdDev	5.112E-03	**90%**	276.897E-03
25%	265.372E-03	**Range**	20.248E-03
Mean+3*StdDev	285.086E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	254.416E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.0363		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

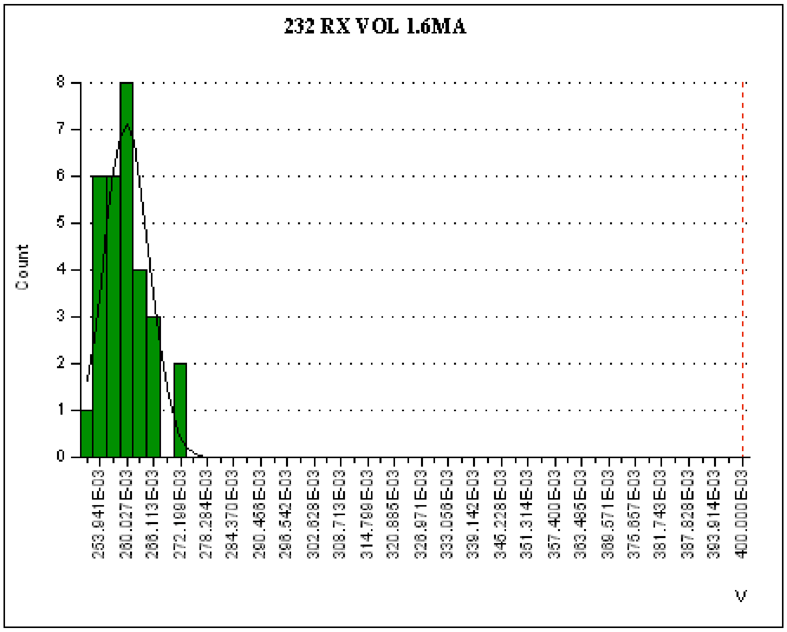
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.008, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

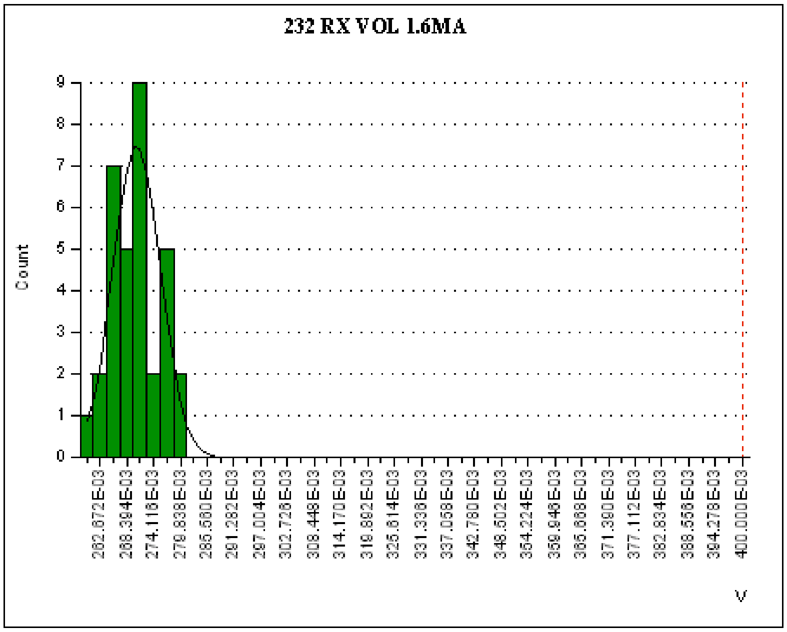
Min	250.898E-03	**Skew**	0.8601
Max	272.647E-03	**StatHigh**	N/A
Mean	259.705E-03	**StatLow**	N/A
StdDev	5.122E-03	**NWithinSpec**	30
25%	256.461E-03	**NOutsideSpec**	0
Mean+3*StdDev	275.071E-03	**90%**	266.384E-03
		Range	21.748E-03
Mean-3*StdDev	244.339E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.008, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	259.811E-03	**StatLow**	N/A
Max	279.756E-03	**NWithinSpec**	33
Mean	270.257E-03	**NOutsideSpec**	0
StdDev	5.008E-03	**90%**	276.367E-03
25%	266.306E-03	**Range**	19.945E-03
Mean+3*StdDev	285.281E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	255.232E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.0174		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

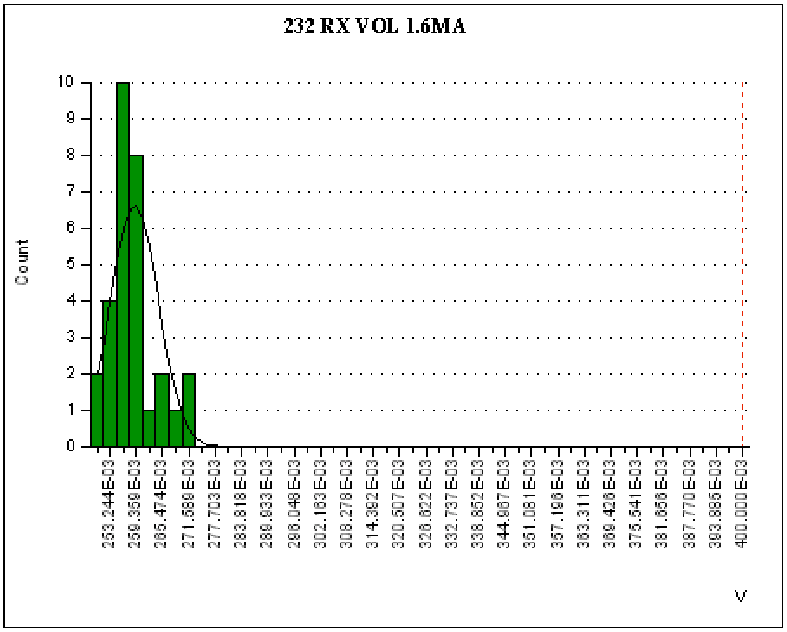
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.009, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

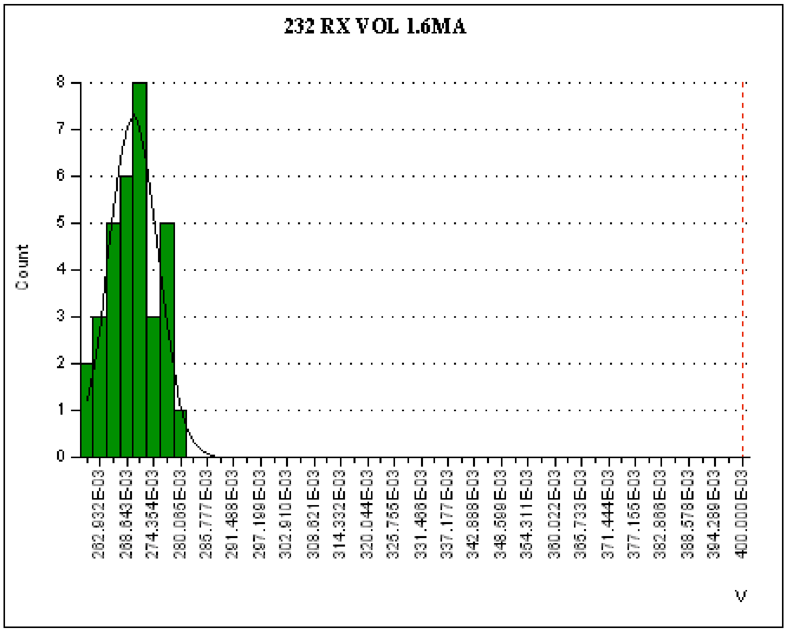
Min	250.187E-03	**Skew**	1.0533
Max	272.405E-03	**StatHigh**	N/A
Mean	258.733E-03	**StatLow**	N/A
StdDev	5.493E-03	**NWithinSpec**	30
25%	255.330E-03	**NOutsideSpec**	0
Mean+3*StdDev	275.211E-03	**90%**	267.299E-03
		Range	22.219E-03
Mean-3*StdDev	242.255E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.009, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	260.076E-03	**StatLow**	N/A
Max	279.642E-03	**NWithinSpec**	33
Mean	269.816E-03	**NOutsideSpec**	0
StdDev	5.128E-03	**90%**	276.481E-03
25%	265.839E-03	**Range**	19.566E-03
Mean+3*StdDev	285.201E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	254.431E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.0240		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

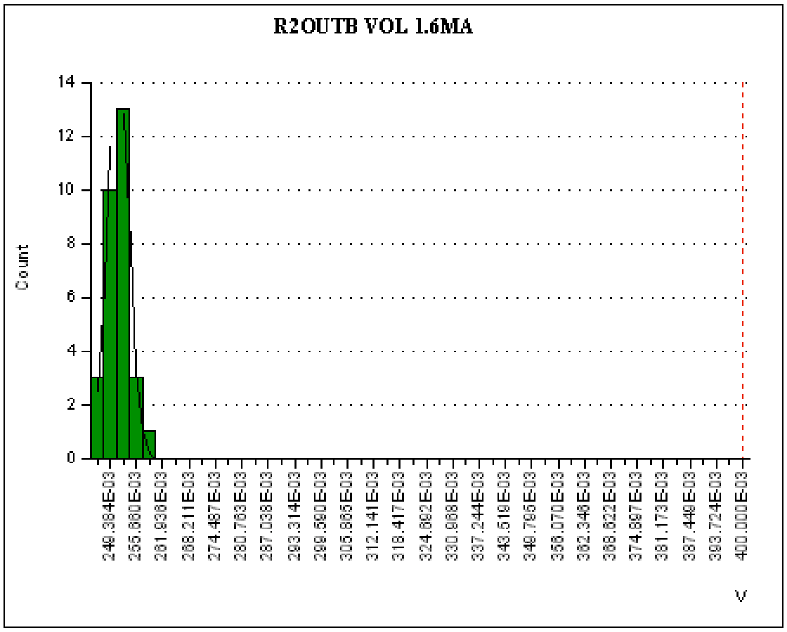
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.010, Test.Name=R2OUTB VOL 1.6MA



Statistics: (V)

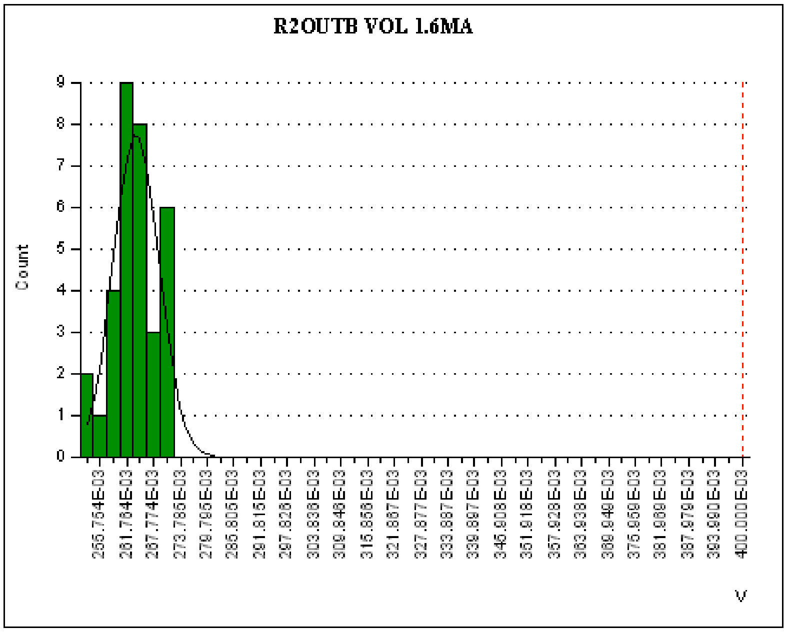
Min	246.247E-03	**Skew**	0.3601
Max	257.986E-03	**StatHigh**	N/A
Mean	251.076E-03	**StatLow**	N/A
StdDev	2.565E-03	**NWithinSpec**	30
25%	249.246E-03	**NOutsideSpec**	0
Mean+3*StdDev	258.771E-03	**90%**	254.181E-03
		Range	11.740E-03
Mean-3*StdDev	243.381E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.010, Test.Name=R2OUTB VOL 1.6MA



Statistics: (V)

Min	252.749E-03	**StatLow**	N/A
Max	271.779E-03	**NWithinSpec**	33
Mean	263.574E-03	**NOutsideSpec**	0
StdDev	5.072E-03	**90%**	270.453E-03
25%	260.506E-03	**Range**	19.030E-03
Mean+3*StdDev	278.791E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	248.357E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.1359		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

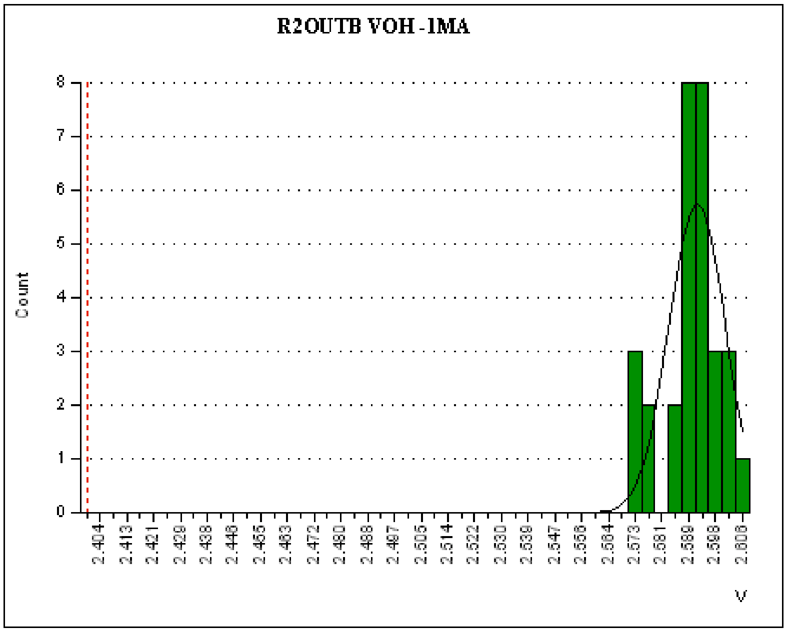
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=3.011, Test.Name=R2OUTB VOH -1MA



Statistics: (V)

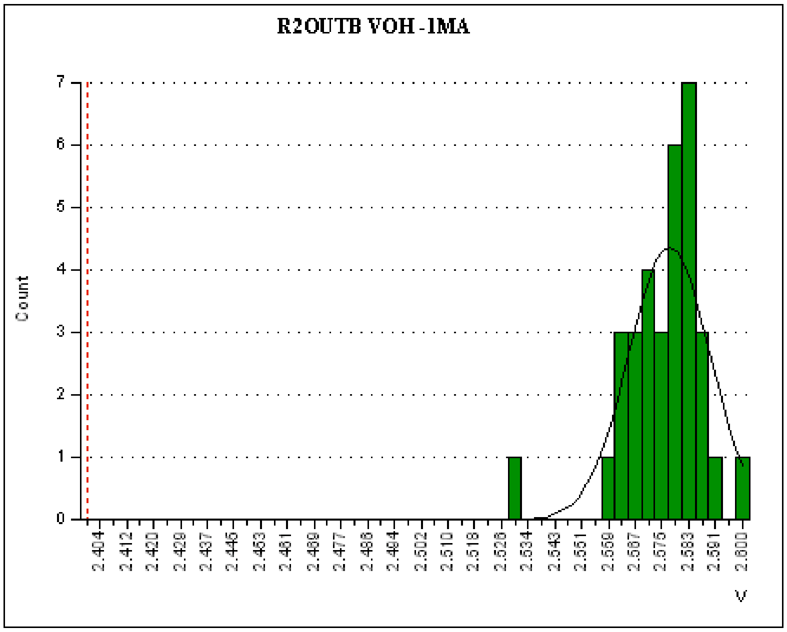
Min	2.572	**Skew**	-0.5384
Max	2.606	**StatHigh**	N/A
Mean	2.590	**StatLow**	N/A
StdDev	8.714E-03	**NWithinSpec**	30
25%	2.587	**NOutsideSpec**	0
Mean+3*StdDev	2.616	**90%**	2.601
		Range	34.607E-03
Mean-3*StdDev	2.564	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.011, Test.Name=R2OUTB VOH -1MA



Statistics: (V)

Min	2.529	**StatLow**	N/A
Max	2.600	**NWithinSpec**	33
Mean	2.575	**NOutsideSpec**	0
StdDev	12.290E-03	**90%**	2.586
25%	2.569	**Range**	70.417E-03
Mean+3*StdDev	2.612	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.539	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-1.5630		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

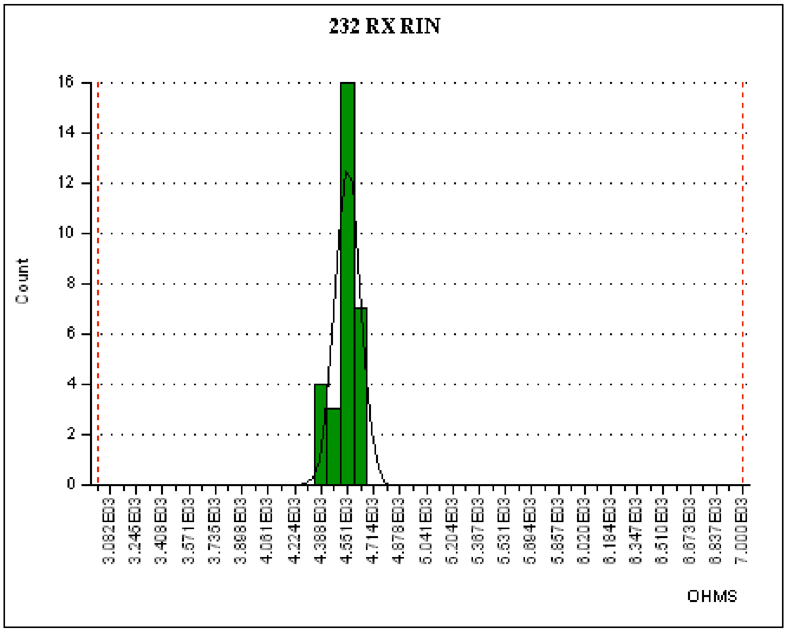
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=4.000, Test.Name=232 RX RIN



Statistics: (OHMS)

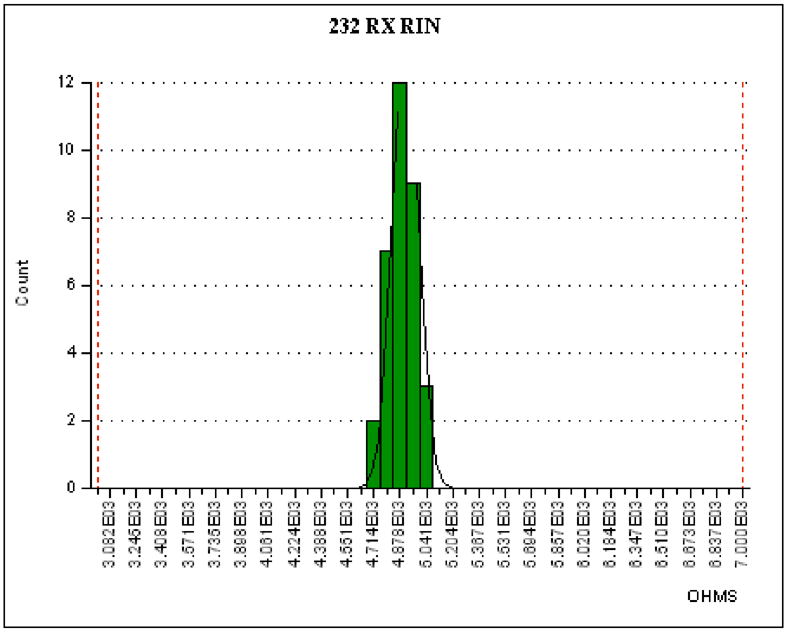
Min	4.353E03	**Skew**	-1.0357
Max	4.642E03	**StatHigh**	N/A
Mean	4.535E03	**StatLow**	N/A
StdDev	76.585	**NWithinSpec**	30
25%	4.522E03	**NOutsideSpec**	0
Mean+3*StdDev	4.765E03	**90%**	4.612E03
		Range	288.949
Mean-3*StdDev	4.305E03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.000, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.736E03	**StatLow**	N/A
Max	5.016E03	**NWithinSpec**	33
Mean	4.889E03	**NOutsideSpec**	0
StdDev	80.116	**90%**	4.999E03
25%	4.831E03	**Range**	279.551
Mean+3*StdDev	5.129E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.648E03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.0077		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

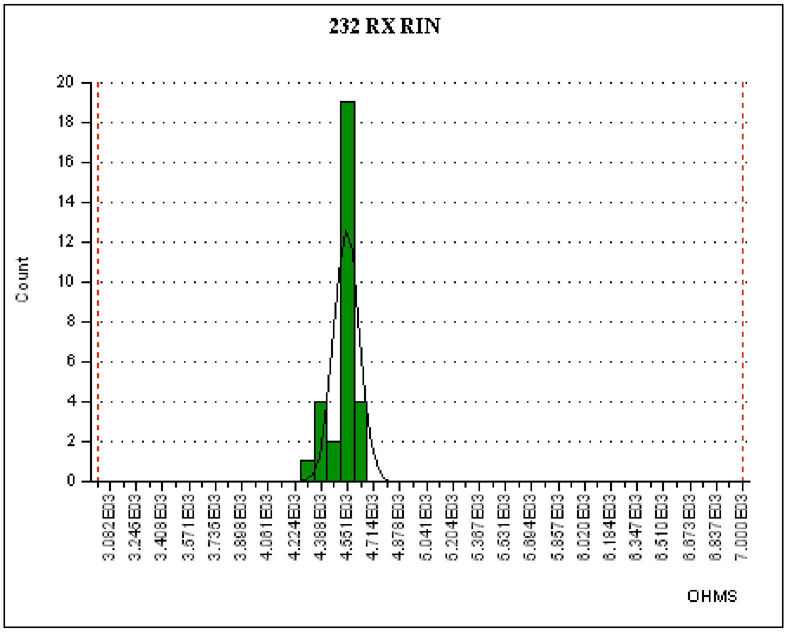
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=4.001, Test.Name=232 RX RIN



Statistics: (OHMS)

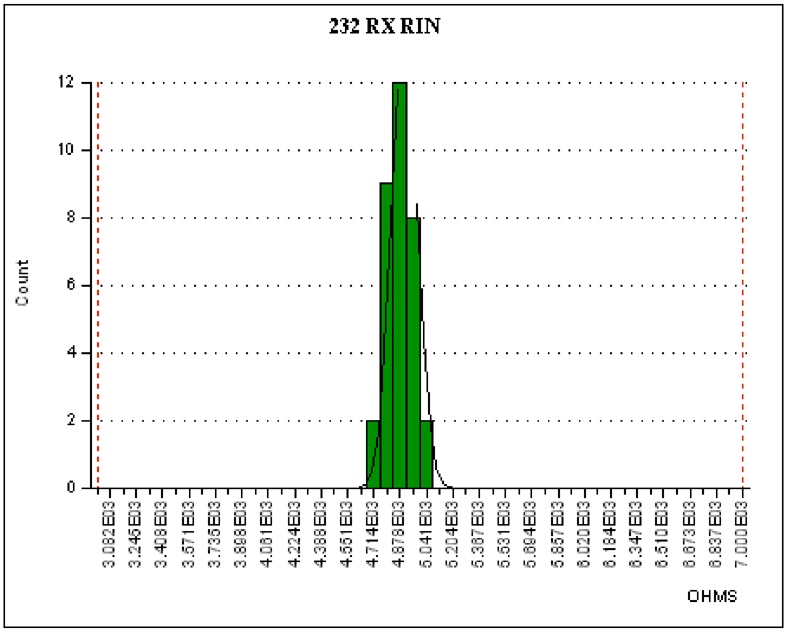
Min	4.338E03	**Skew**	-1.0846
Max	4.632E03	**StatHigh**	N/A
Mean	4.527E03	**StatLow**	N/A
StdDev	77.212	**NWithinSpec**	30
25%	4.512E03	**NOutsideSpec**	0
Mean+3*StdDev	4.759E03	**90%**	4.604E03
		Range	294.375
Mean-3*StdDev	4.296E03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.001, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.731E03	**StatLow**	N/A
Max	5.013E03	**NWithinSpec**	33
Mean	4.882E03	**NOutsideSpec**	0
StdDev	78.887	**90%**	4.991E03
25%	4.825E03	**Range**	281.656
Mean+3*StdDev	5.119E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.646E03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.1066		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

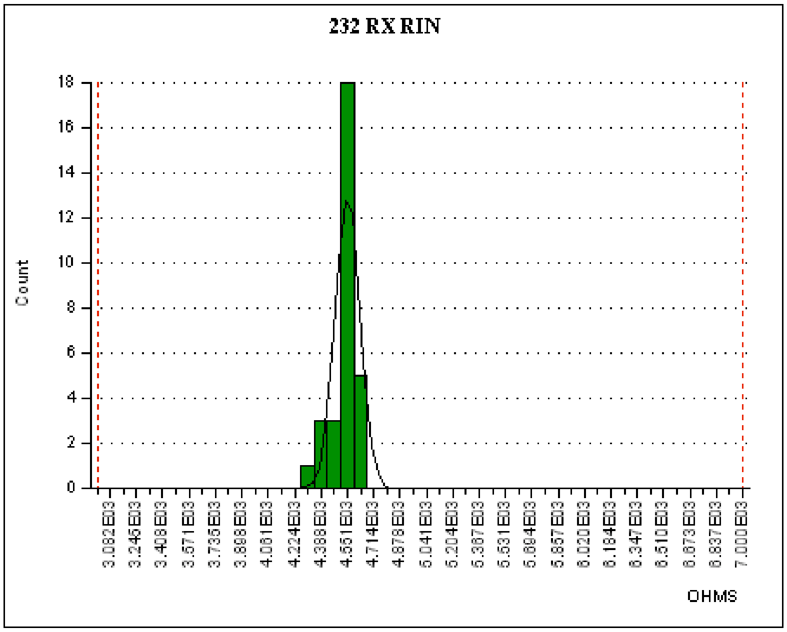
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=4.002, Test.Name=232 RX RIN



Statistics: (OHMS)

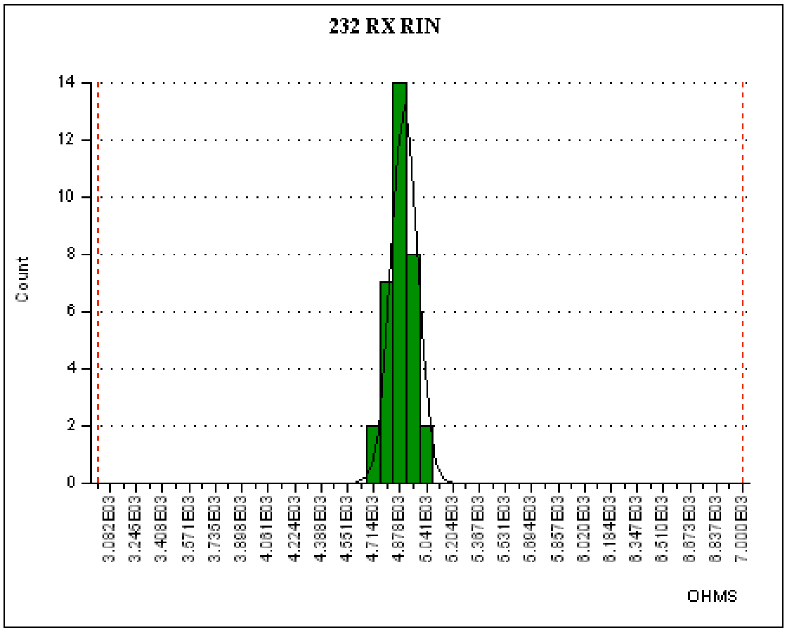
Min	4.347E03	**Skew**	-1.1015
Max	4.641E03	**StatHigh**	N/A
Mean	4.534E03	**StatLow**	N/A
StdDev	75.122	**NWithinSpec**	30
25%	4.516E03	**NOutsideSpec**	0
Mean+3*StdDev	4.759E03	**90%**	4.611E03
		Range	294.895
Mean-3*StdDev	4.308E03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.002, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.729E03	**StatLow**	N/A
Max	5.017E03	**NWithinSpec**	33
Mean	4.882E03	**NOutsideSpec**	0
StdDev	81.339	**90%**	4.996E03
25%	4.826E03	**Range**	287.863
Mean+3*StdDev	5.126E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.638E03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.1004		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

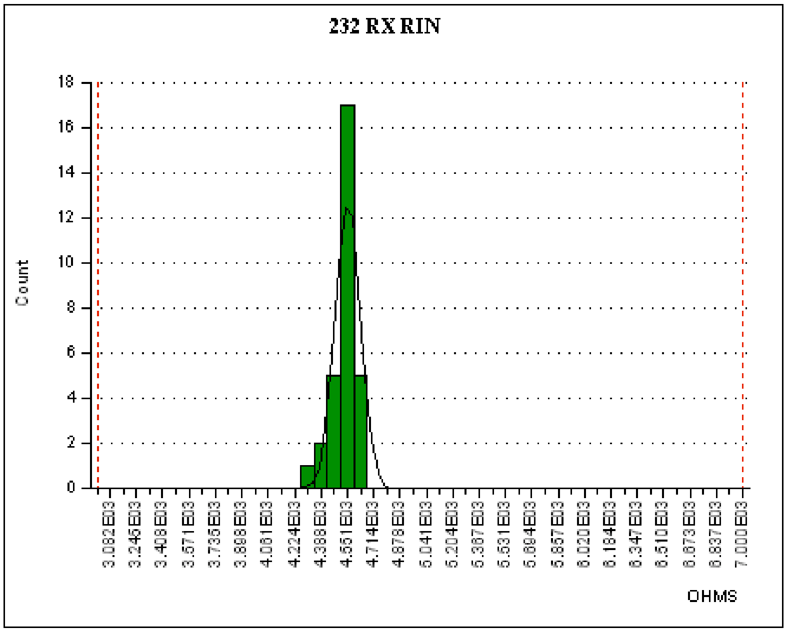
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=4.003, Test.Name=232 RX RIN



Statistics: (OHMS)

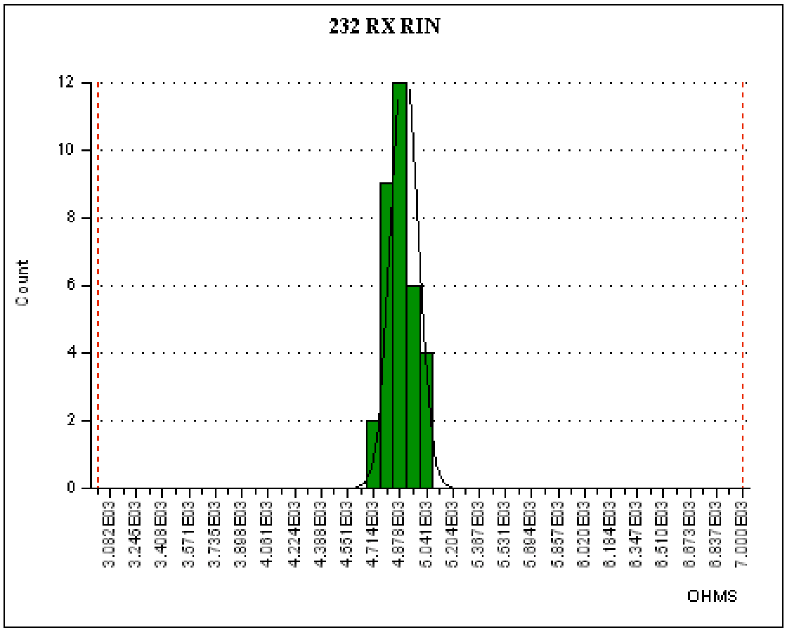
Min	4.326E03	**Skew**	-1.1405
Max	4.641E03	**StatHigh**	N/A
Mean	4.535E03	**StatLow**	N/A
StdDev	76.840	**NWithinSpec**	30
25%	4.504E03	**NOutsideSpec**	0
Mean+3*StdDev	4.765E03	**90%**	4.607E03
		Range	314.914
Mean-3*StdDev	4.304E03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.003, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.730E03	**StatLow**	N/A
Max	5.011E03	**NWithinSpec**	33
Mean	4.882E03	**NOutsideSpec**	0
StdDev	81.873	**90%**	5.004E03
25%	4.829E03	**Range**	280.578
Mean+3*StdDev	5.128E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.637E03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.1044		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

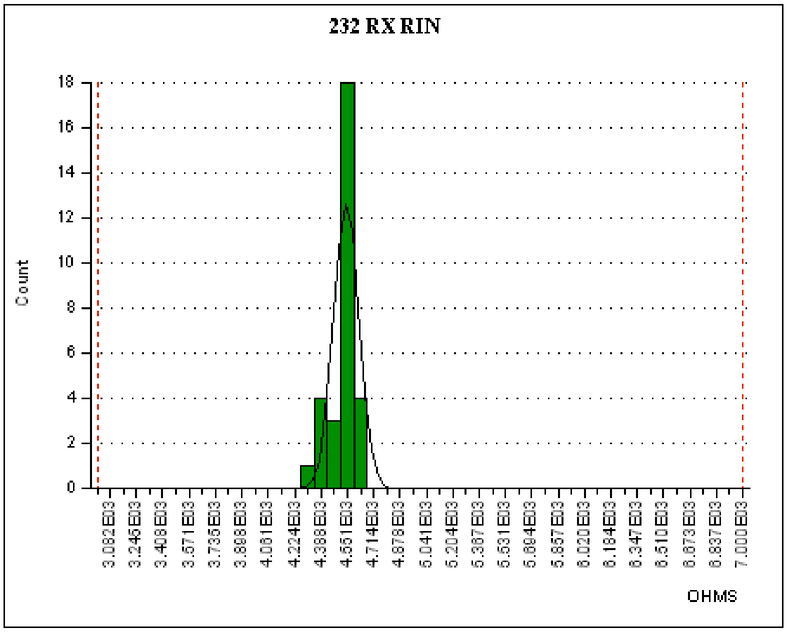
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=4.004, Test.Name=232 RX RIN



Statistics: (OHMS)

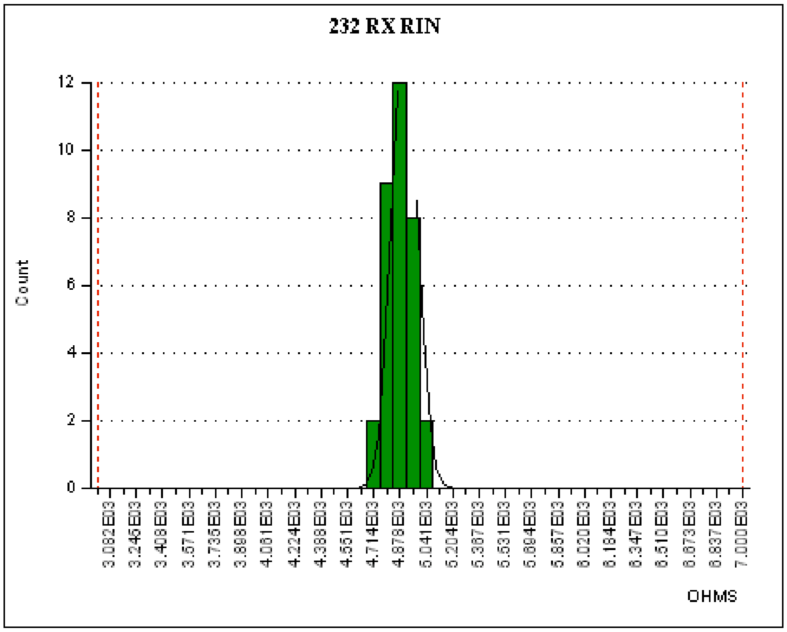
Min	4.310E03	**Skew**	-1.1715
Max	4.632E03	**StatHigh**	N/A
Mean	4.526E03	**StatLow**	N/A
StdDev	77.156	**NWithinSpec**	30
25%	4.509E03	**NOutsideSpec**	0
Mean+3*StdDev	4.757E03	**90%**	4.602E03
		Range	321.523
Mean-3*StdDev	4.294E03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.004, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.740E03	**StatLow**	N/A
Max	5.025E03	**NWithinSpec**	33
Mean	4.883E03	**NOutsideSpec**	0
StdDev	78.411	**90%**	4.997E03
25%	4.831E03	**Range**	285.379
Mean+3*StdDev	5.119E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.648E03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.1583		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

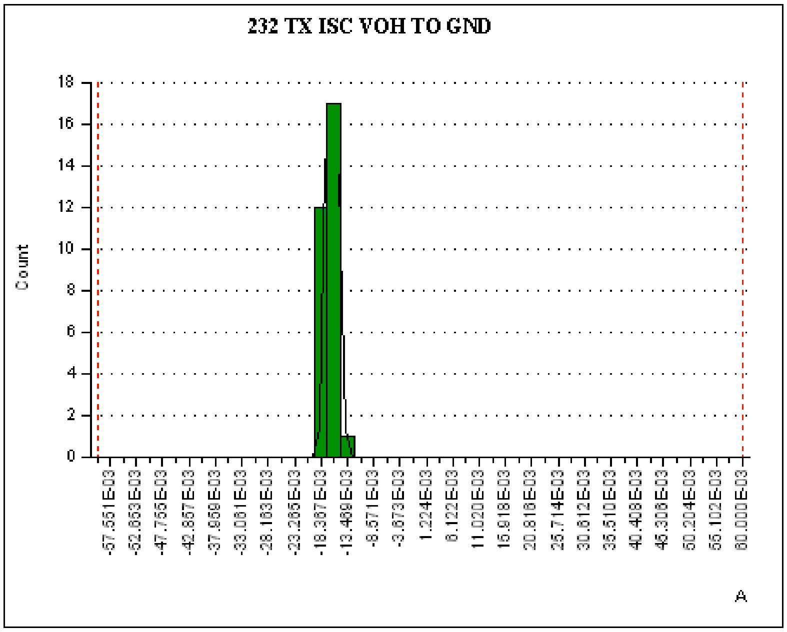
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=6.000, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

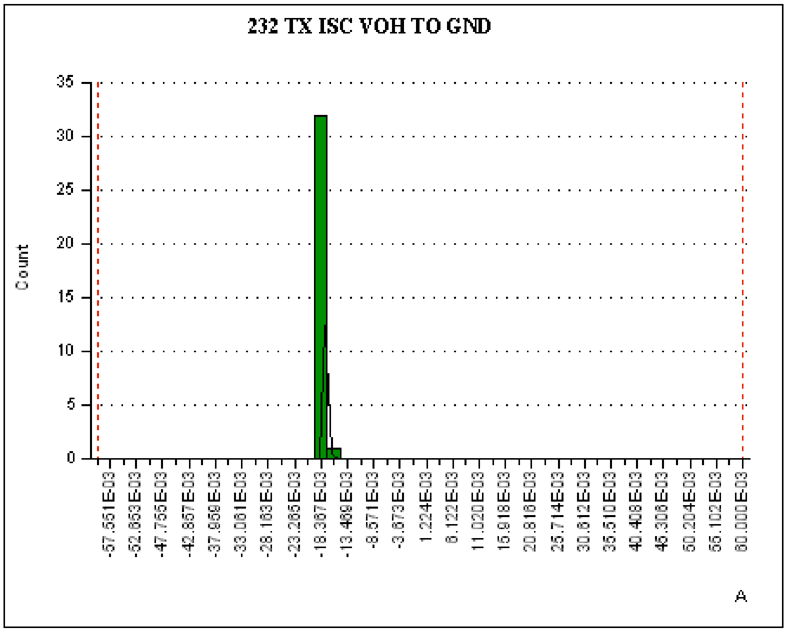
Min	-18.154E-03	**Skew**	0.5636
Max	-14.146E-03	**StatHigh**	N/A
Mean	-16.820E-03	**StatLow**	N/A
StdDev	959.638E-06	**NWithinSpec**	30
25%	-17.687E-03	**NOutsideSpec**	0
Mean+3*StdDev	-13.941E-03	**90%**	-15.822E-03
		Range	4.008E-03
Mean-3*StdDev	-19.699E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.000, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-18.105E-03	**StatLow**	N/A
Max	-17.081E-03	**NWithinSpec**	33
Mean	-17.524E-03	**NOutsideSpec**	0
StdDev	212.550E-06	**90%**	-17.309E-03
25%	-17.645E-03	**Range**	1.024E-03
Mean+3*StdDev	-16.886E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-18.162E-03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.5551		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

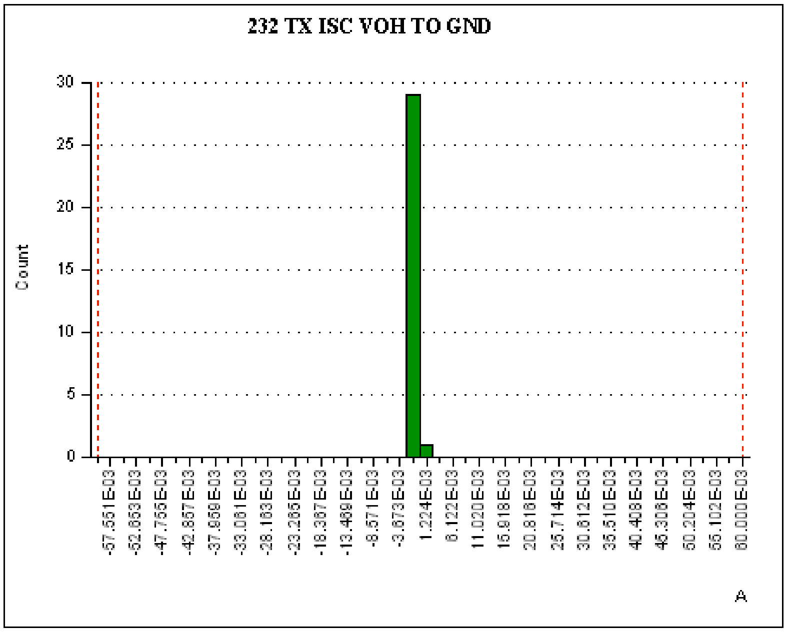
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=6.001, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

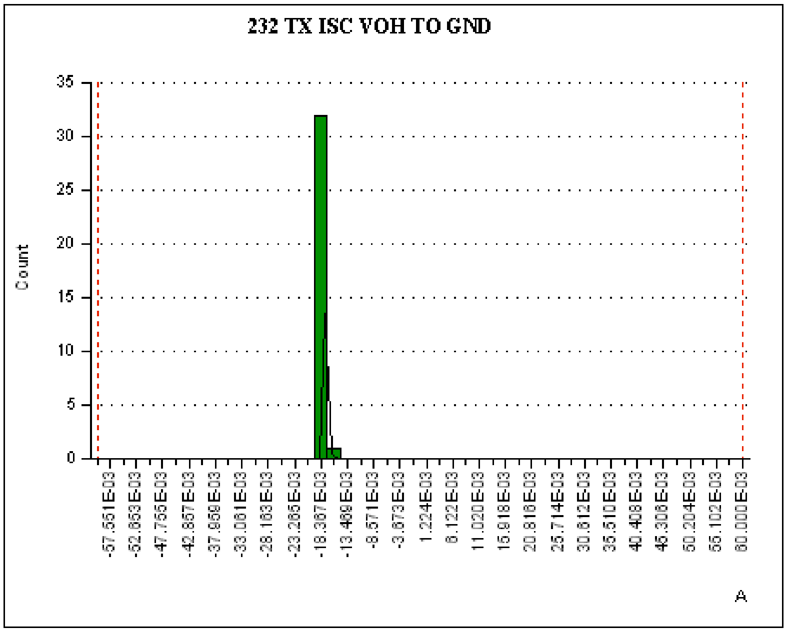
Min	-37.907E-06	**Skew**	-0.5738
Max	187.507E-09	**StatHigh**	N/A
Mean	-16.216E-06	**StatLow**	N/A
StdDev	9.440E-06	**NWithinSpec**	30
25%	-21.250E-06	**NOutsideSpec**	0
Mean+3*StdDev	12.104E-06	**90%**	-5.916E-06
		Range	38.095E-06
Mean-3*StdDev	-44.536E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.001, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-18.120E-03	**StatLow**	N/A
Max	-17.050E-03	**NWithinSpec**	33
Mean	-17.531E-03	**NOutsideSpec**	0
StdDev	213.672E-06	**90%**	-17.310E-03
25%	-17.649E-03	**Range**	1.070E-03
Mean+3*StdDev	-16.890E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-18.172E-03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.4884		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

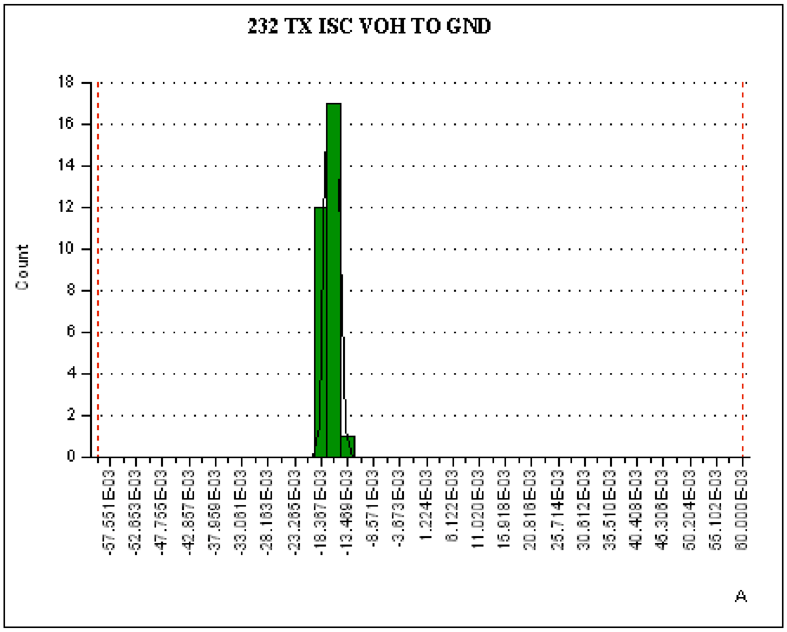
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=6.002, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

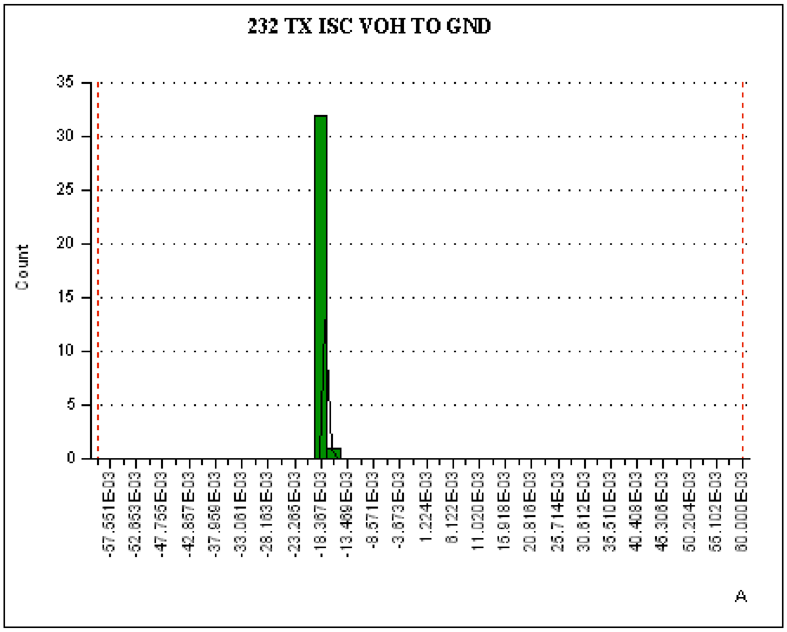
Min	-18.158E-03	**Skew**	0.6188
Max	-14.126E-03	**StatHigh**	N/A
Mean	-16.838E-03	**StatLow**	N/A
StdDev	961.393E-06	**NWithinSpec**	30
25%	-17.706E-03	**NOutsideSpec**	0
Mean+3*StdDev	-13.953E-03	**90%**	-15.831E-03
		Range	4.032E-03
Mean-3*StdDev	-19.722E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.002, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-18.073E-03	**StatLow**	N/A
Max	-16.958E-03	**NWithinSpec**	33
Mean	-17.514E-03	**NOutsideSpec**	0
StdDev	220.009E-06	**90%**	-17.304E-03
25%	-17.638E-03	**Range**	1.116E-03
Mean+3*StdDev	-16.854E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-18.174E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.2786		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

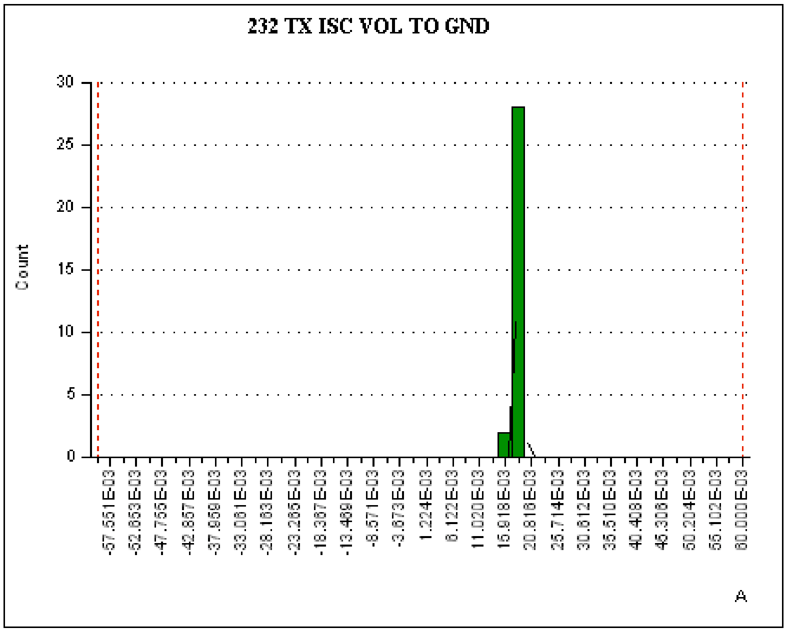
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=6.003, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

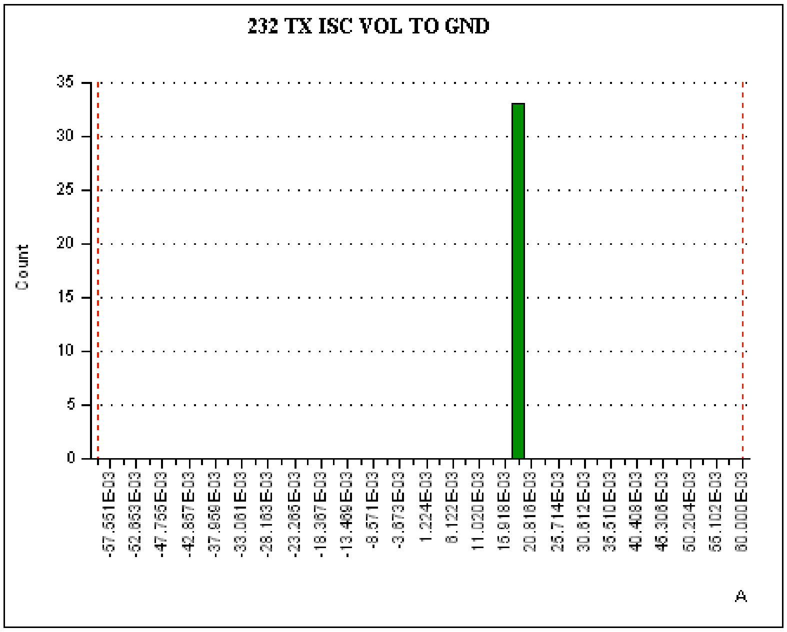
Min	16.096E-03	**Skew**	-0.8969
Max	18.551E-03	**StatHigh**	N/A
Mean	17.744E-03	**StatLow**	N/A
StdDev	521.131E-06	**NWithinSpec**	30
25%	17.394E-03	**NOutsideSpec**	0
Mean+3*StdDev	19.308E-03	**90%**	18.406E-03
		Range	2.455E-03
Mean-3*StdDev	16.181E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.003, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	17.618E-03	**StatLow**	N/A
Max	18.445E-03	**NWithinSpec**	33
Mean	17.906E-03	**NOutsideSpec**	0
StdDev	207.095E-06	**90%**	18.186E-03
25%	17.753E-03	**Range**	827.242E-06
Mean+3*StdDev	18.528E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	17.285E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.7771		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

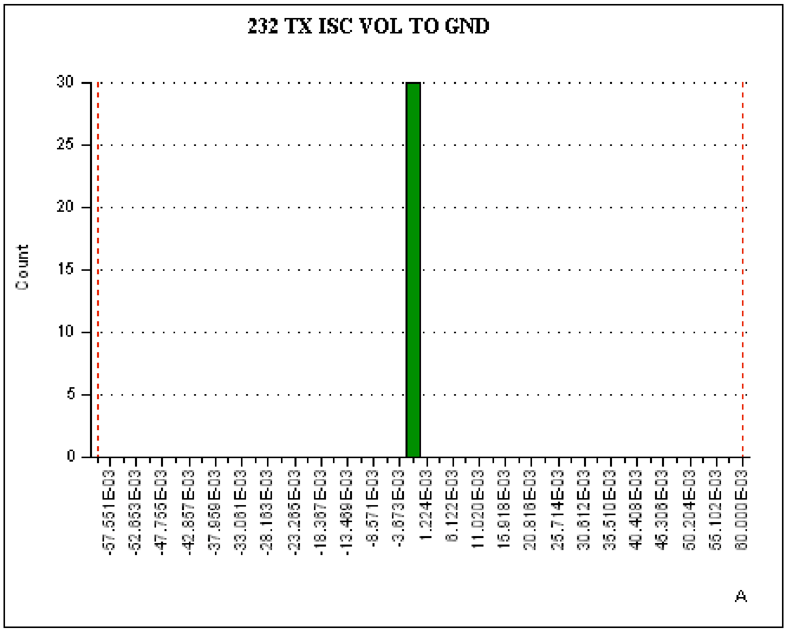
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=6.004, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

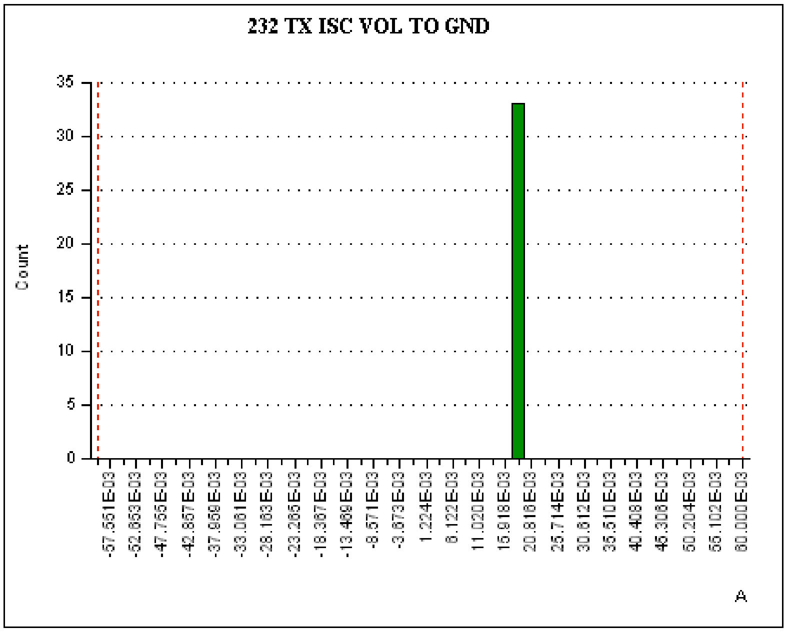
Min	-31.059E-06	**Skew**	-0.3397
Max	-2.789E-06	**StatHigh**	N/A
Mean	-13.885E-06	**StatLow**	N/A
StdDev	7.270E-06	**NWithinSpec**	30
25%	-18.868E-06	**NOutsideSpec**	0
Mean+3*StdDev	7.926E-06	**90%**	-4.130E-06
		Range	28.270E-06
Mean-3*StdDev	-35.697E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.004, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	17.636E-03	**StatLow**	N/A
Max	18.476E-03	**NWithinSpec**	33
Mean	17.929E-03	**NOutsideSpec**	0
StdDev	209.418E-06	**90%**	18.220E-03
25%	17.759E-03	**Range**	839.975E-06
Mean+3*StdDev	18.557E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	17.301E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.7833		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

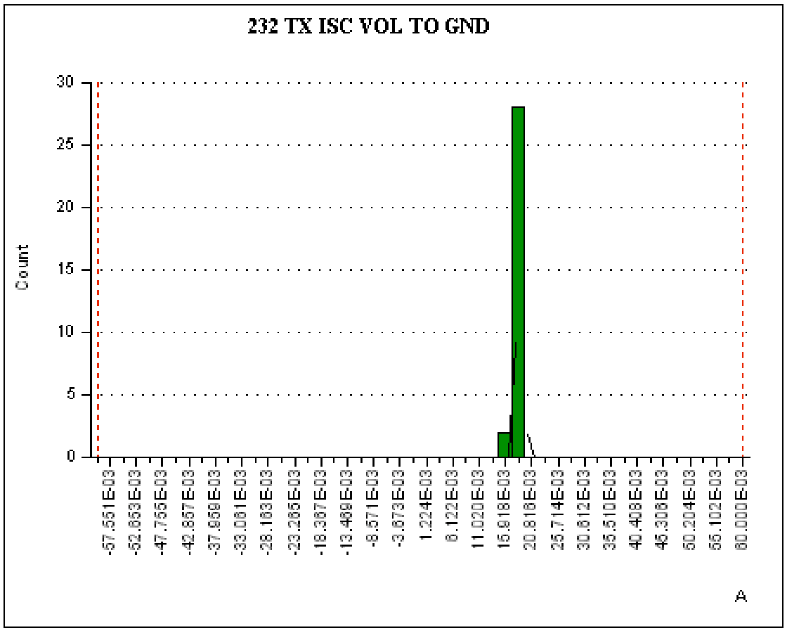
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=6.005, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

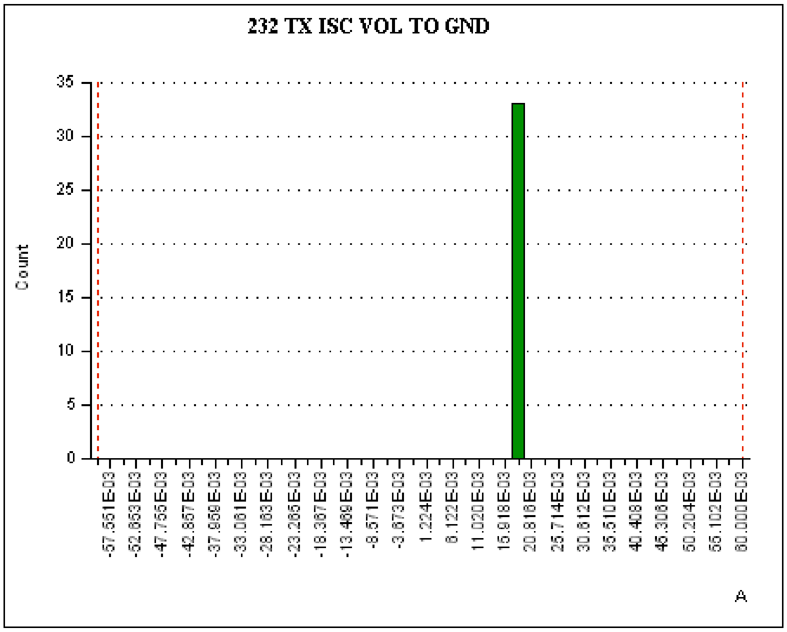
Min	16.146E-03	**Skew**	-0.8624
Max	18.617E-03	**StatHigh**	N/A
Mean	17.807E-03	**StatLow**	N/A
StdDev	531.071E-06	**NWithinSpec**	30
25%	17.414E-03	**NOutsideSpec**	0
Mean+3*StdDev	19.401E-03	**90%**	18.484E-03
		Range	2.471E-03
Mean-3*StdDev	16.214E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.005, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	17.682E-03	**StatLow**	N/A
Max	18.533E-03	**NWithinSpec**	33
Mean	17.969E-03	**NOutsideSpec**	0
StdDev	211.043E-06	**90%**	18.257E-03
25%	17.800E-03	**Range**	850.927E-06
Mean+3*StdDev	18.602E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	17.336E-03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.8048		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

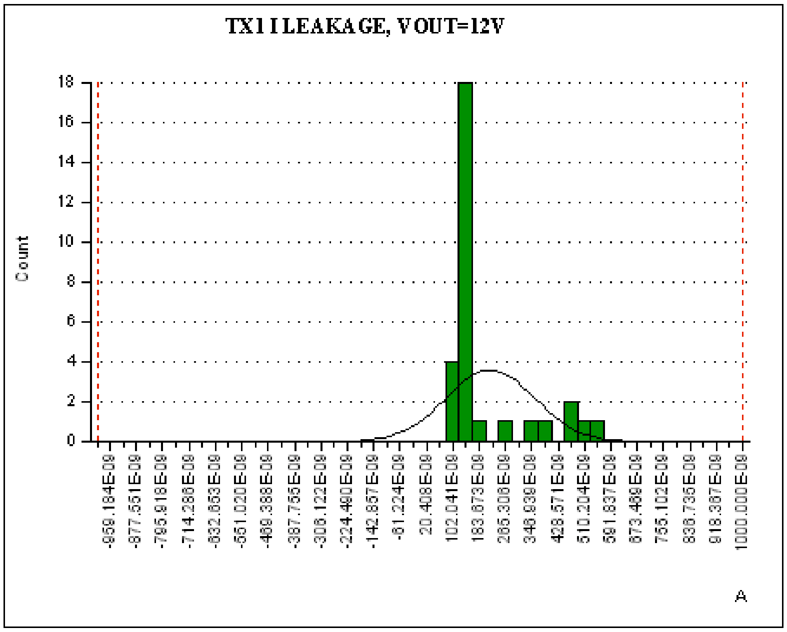
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=8.003, Test.Name=TX1 I LEAKAGE, VOUT=12V



Statistics: (A)

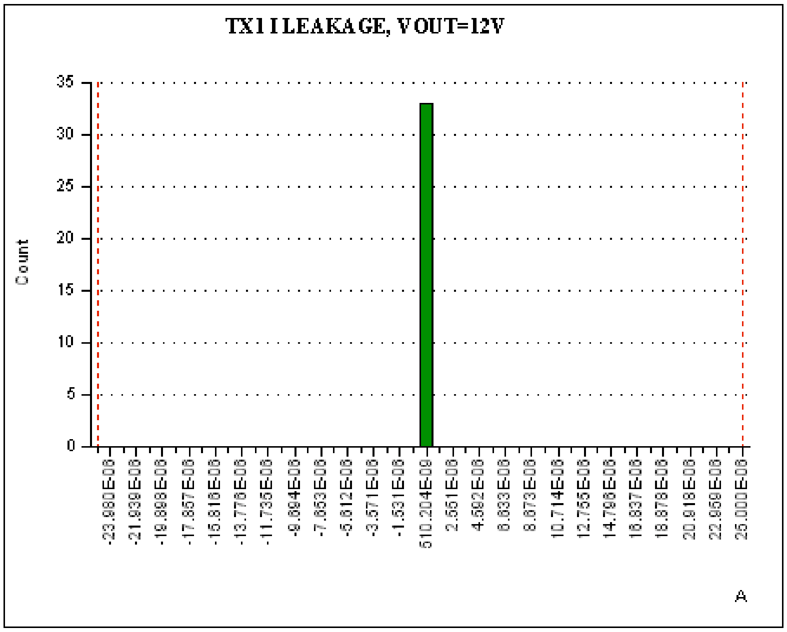
Min	95.906E-09	**Skew**	1.6756
Max	568.518E-09	**StatHigh**	N/A
Mean	205.051E-09	**StatLow**	N/A
StdDev	135.290E-09	**NWithinSpec**	30
25%	131.353E-09	**NOutsideSpec**	0
Mean+3*StdDev	610.923E-09	**90%**	462.817E-09
		Range	472.612E-09
Mean-3*StdDev	-200.820E-09	**NOutsideSpec**	0
Cpk	1.9586		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.003, Test.Name=TX1 I LEAKAGE, VOUT=12V



Statistics: (A)

Min	20.429E-09	**StatLow**	N/A
Max	451.769E-09	**NWithinSpec**	33
Mean	119.754E-09	**NOutsideSpec**	0
StdDev	82.462E-09	**90%**	227.556E-09
25%	74.433E-09	**Range**	431.340E-09
Mean+3*StdDev	367.141E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-127.633E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	2.4118		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

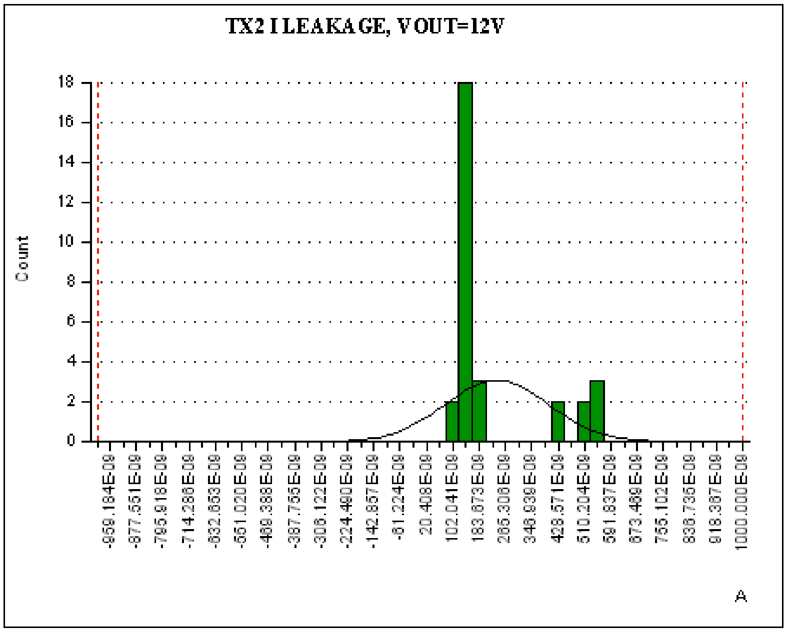
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=8.004, Test.Name=TX2 I LEAKAGE, VOUT=12V



Statistics: (A)

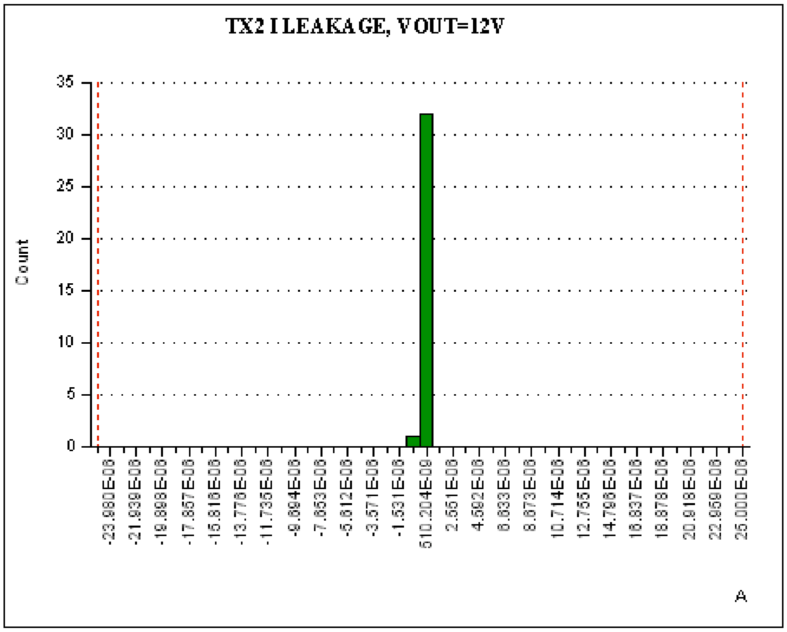
Min	95.911E-09	**Skew**	1.4051
Max	559.884E-09	**StatHigh**	N/A
Mean	226.030E-09	**StatLow**	N/A
StdDev	158.530E-09	**NWithinSpec**	30
25%	136.456E-09	**NOutsideSpec**	0
Mean+3*StdDev	701.619E-09	**90%**	536.168E-09
		Range	463.973E-09
Mean-3*StdDev	-249.559E-09	**NOutsideSpec**	0
Cpk	1.6274		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.004, Test.Name=TX2 I LEAKAGE, VOUT=12V



Statistics: (A)

Min	-17.216E-09	**StatLow**	N/A
Max	410.705E-09	**NWithinSpec**	33
Mean	119.519E-09	**NOutsideSpec**	0
StdDev	80.413E-09	**90%**	209.928E-09
25%	70.526E-09	**Range**	427.921E-09
Mean+3*StdDev	360.758E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-121.721E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	1.6926		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

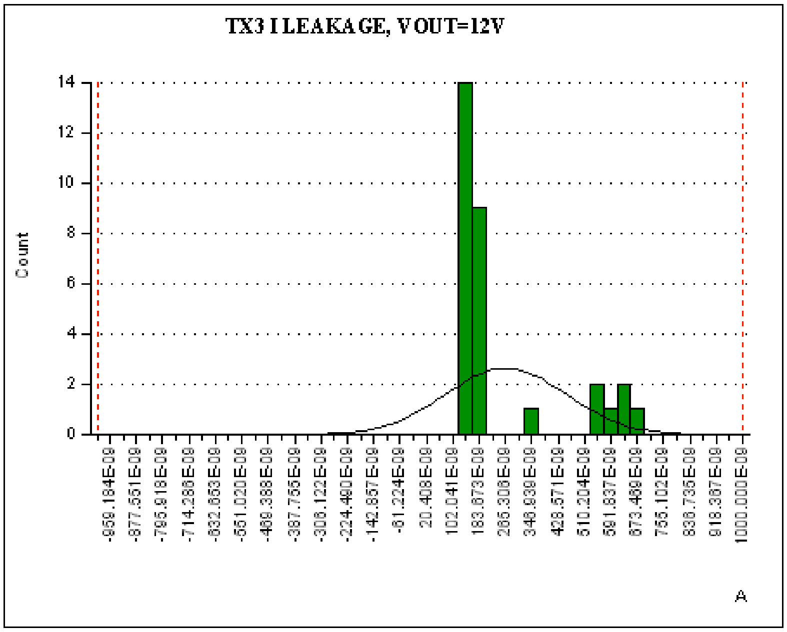
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=8.005, Test.Name=TX3 I LEAKAGE, VOUT=12V



Statistics: (A)

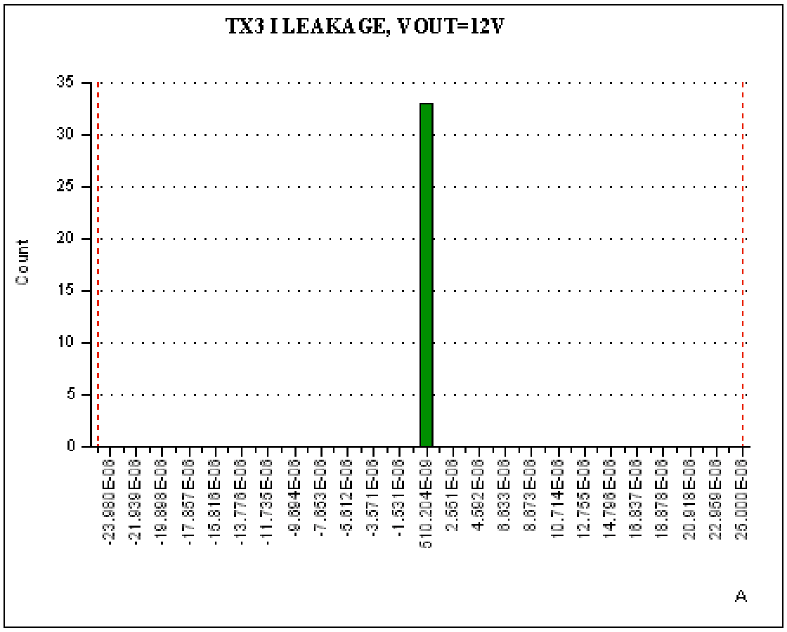
Min	129.492E-09	**Skew**	1.5110
Max	676.444E-09	**StatHigh**	N/A
Mean	254.216E-09	**StatLow**	N/A
StdDev	184.568E-09	**NWithinSpec**	30
25%	151.290E-09	**NOutsideSpec**	0
Mean+3*StdDev	807.919E-09	**90%**	612.079E-09
		Range	546.952E-09
Mean-3*StdDev	-299.487E-09	**NOutsideSpec**	0
Cpk	1.3469		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.005, Test.Name=TX3 I LEAKAGE, VOUT=12V



Statistics: (A)

Min	23.022E-09	**StatLow**	N/A
Max	319.108E-09	**NWithinSpec**	33
Mean	114.553E-09	**NOutsideSpec**	0
StdDev	73.723E-09	**90%**	232.147E-09
25%	66.130E-09	**Range**	296.086E-09
Mean+3*StdDev	335.723E-09	**NOutsideSpec**	0
Mean-3*StdDev	-106.616E-09	**Cp**	>4.0000
Cpk	>4.0000	**Cpl**	>4.0000
Skew	1.2635	**Cpu**	>4.0000
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

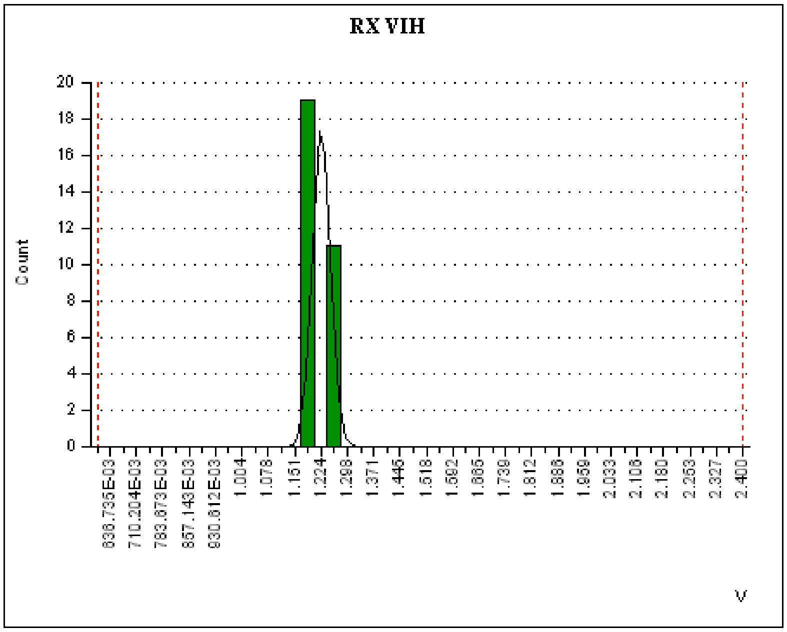
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.000, Test.Name=RX VIH



Statistics: (V)

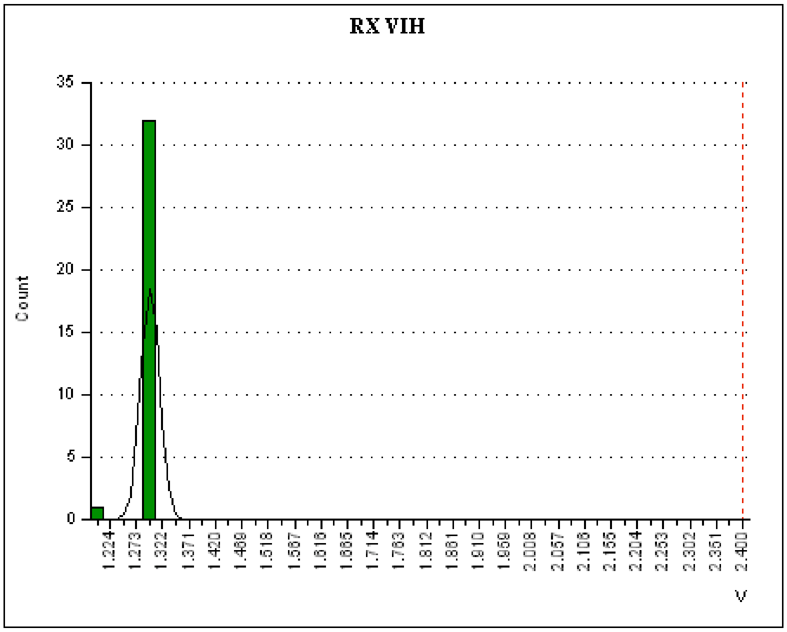
Min	1.200	**Skew**	0.5829
Max	1.250	**StatHigh**	N/A
Mean	1.218	**StatLow**	N/A
StdDev	24.507E-03	**NWithinSpec**	30
25%	1.200	**NOutsideSpec**	0
Mean+3*StdDev	1.292	**90%**	1.250
		Range	50.000E-03
Mean-3*StdDev	1.145	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.000, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.300	**NWithinSpec**	33
Mean	1.297	**NOutsideSpec**	0
StdDev	17.408E-03	**90%**	1.300
25%	1.300	**Range**	100.000E-03
Mean+3*StdDev	1.349	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.245	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-5.7446		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

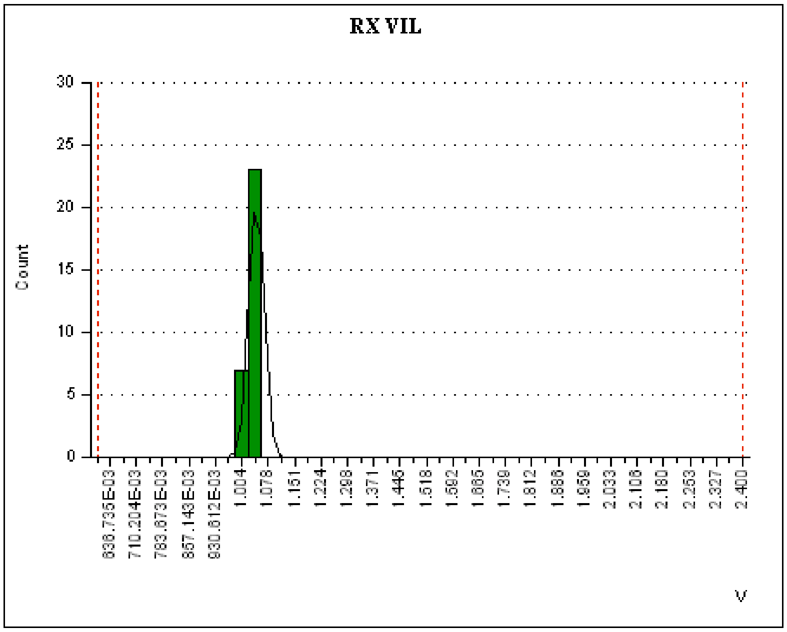
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.001, Test.Name=RX VIL



Statistics: (V)

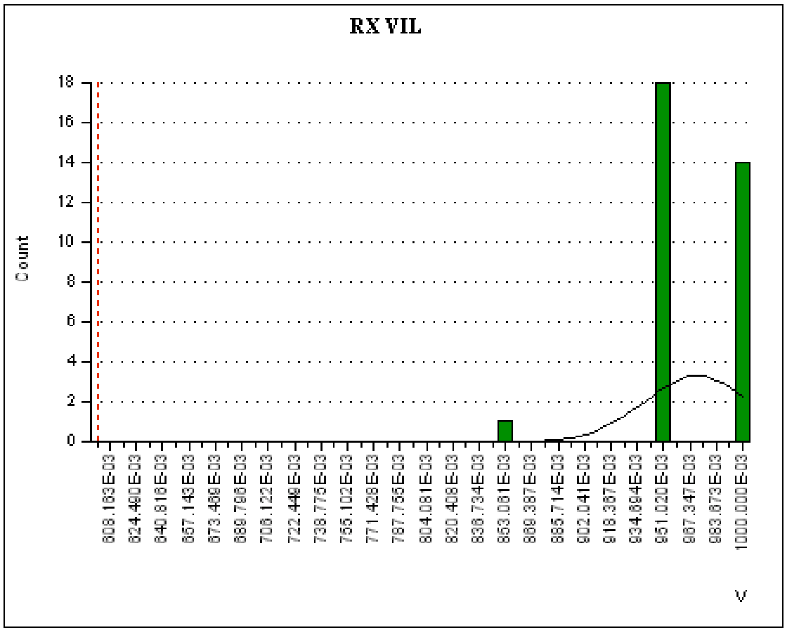
Min	1000.000E-03	**Skew**	-1.3283
Max	1.050	**StatHigh**	N/A
Mean	1.038	**StatLow**	N/A
StdDev	21.509E-03	**NWithinSpec**	30
25%	1.050	**NOutsideSpec**	0
Mean+3*StdDev	1.103	**90%**	1.050
		Range	50.000E-03
Mean-3*StdDev	973.806E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.001, Test.Name=RX VIL



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	33
Mean	968.181E-03	**NOutsideSpec**	0
StdDev	32.640E-03	**90%**	1000.000E-03
25%	950.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.066	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	870.263E-03	**Cpl**	3.7601
		Cpu	N/A
Cpk	3.7601		
Skew	-1.2512		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

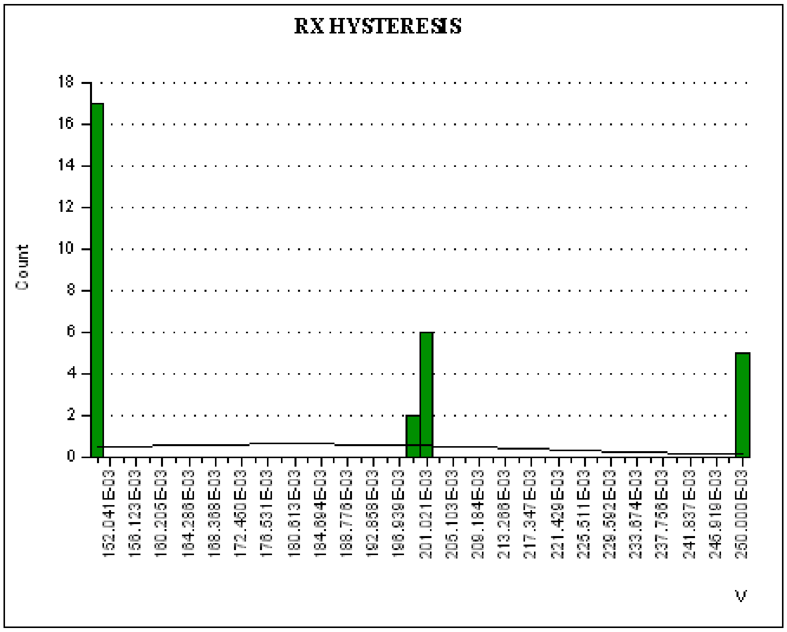
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.002, Test.Name=RX HYSTERESIS



Statistics: (V)

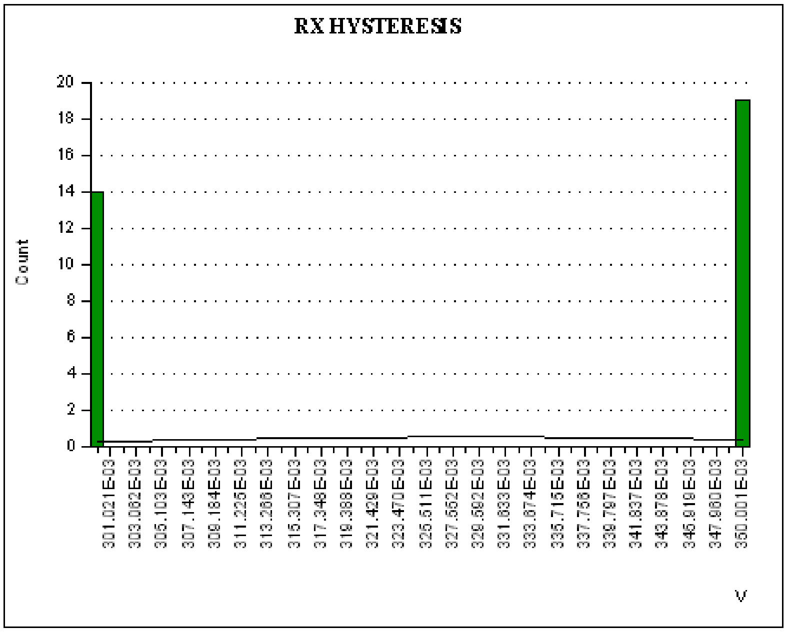
Min	150.001E-03	**Skew**	0.8541
Max	250.000E-03	**StatHigh**	N/A
Mean	180.001E-03	**StatLow**	N/A
StdDev	38.507E-03	**NWithinSpec**	N/A
25%	150.001E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	295.520E-03	**90%**	250.000E-03
		Range	100.000E-03
Mean-3*StdDev	64.481E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.002, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	300.001E-03	**StatLow**	N/A
Max	350.001E-03	**NWithinSpec**	N/A
Mean	328.788E-03	**NOutsideSpec**	N/A
StdDev	25.095E-03	**90%**	350.001E-03
25%	300.001E-03	**Range**	50.000E-03
Mean+3*StdDev	404.072E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	253.505E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.3214		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

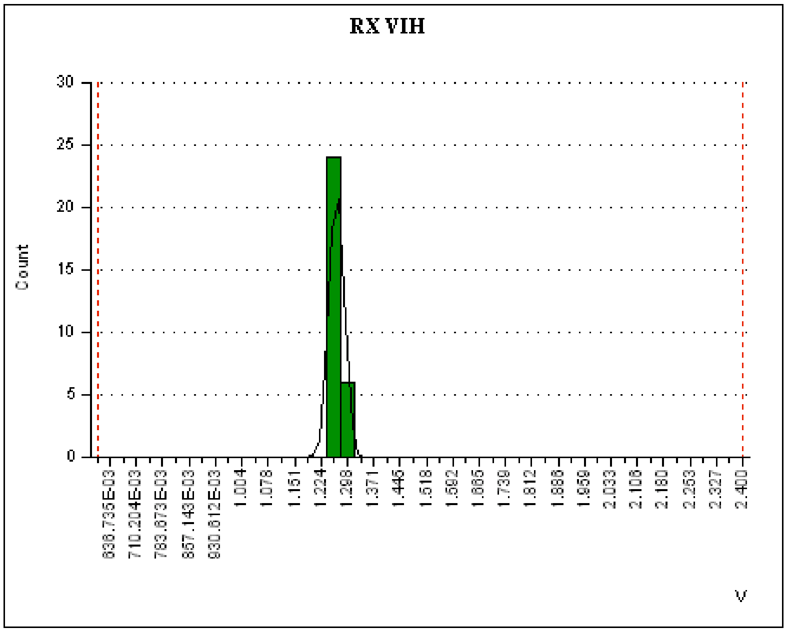
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.003, Test.Name=RX VIH



Statistics: (V)

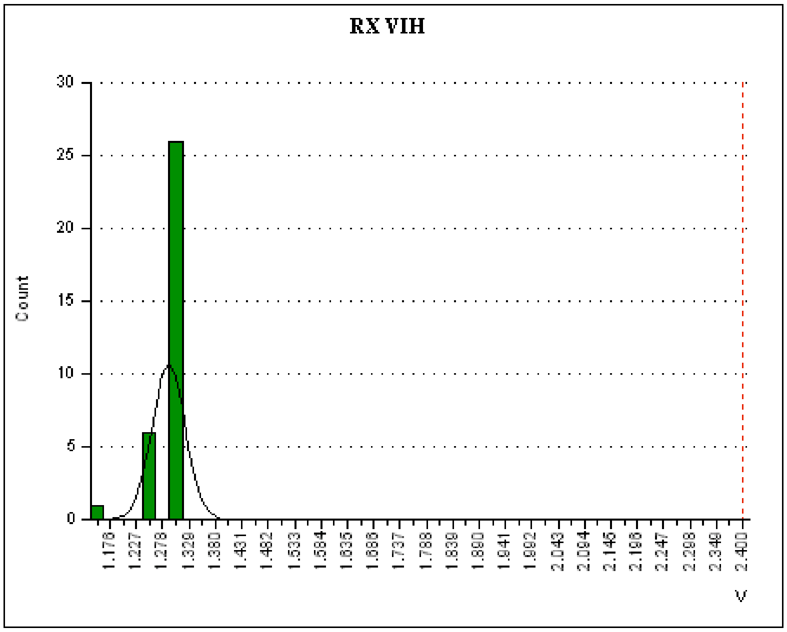
Min	1.250	**Skew**	1.5801
Max	1.300	**StatHigh**	N/A
Mean	1.260	**StatLow**	N/A
StdDev	20.342E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.321	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.199	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.003, Test.Name=RX VIH



Statistics: (V)

Min	1.150	**StatLow**	N/A
Max	1.300	**NWithinSpec**	33
Mean	1.286	**NOutsideSpec**	0
StdDev	31.307E-03	**90%**	1.300
25%	1.300	**Range**	150.001E-03
Mean+3*StdDev	1.380	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.192	**Cpl**	N/A
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-2.9904		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

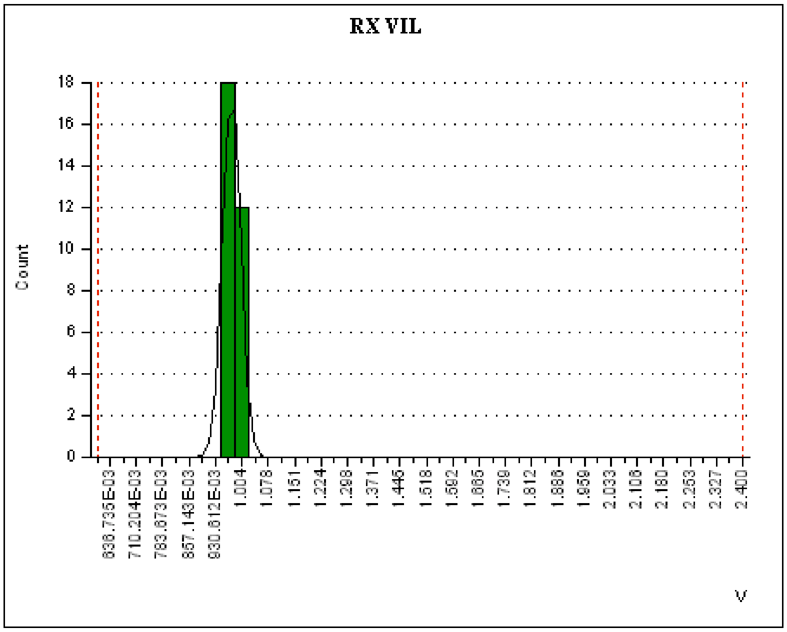
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.004, Test.Name=RX VIL



Statistics: (V)

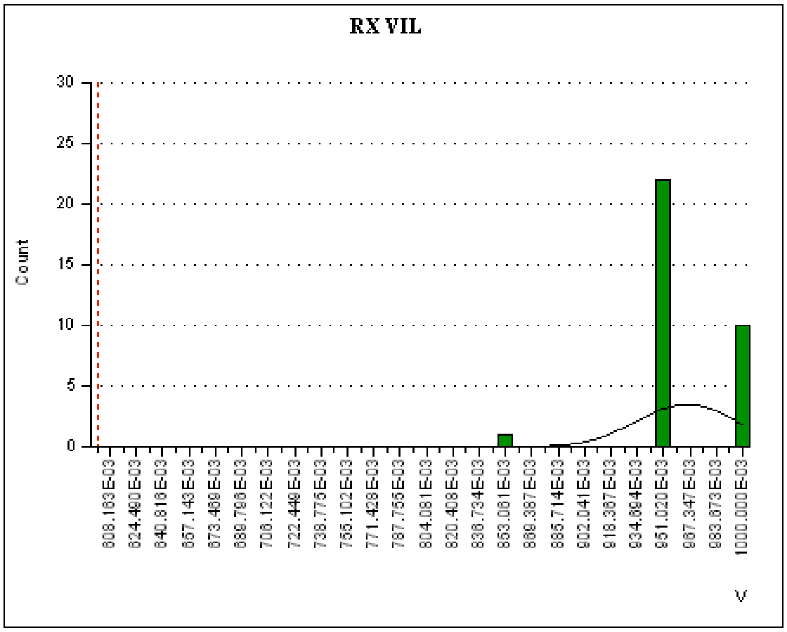
Min	950.000E-03	**Skew**	0.4301
Max	1000.000E-03	**StatHigh**	N/A
Mean	970.000E-03	**StatLow**	N/A
StdDev	24.914E-03	**NWithinSpec**	30
25%	950.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	1.045	**90%**	1000.000E-03
		Range	50.000E-03
Mean-3*StdDev	895.259E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.004, Test.Name=RX VIL



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	33
Mean	962.121E-03	**NOutsideSpec**	0
StdDev	30.696E-03	**90%**	1000.000E-03
25%	950.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.054	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	870.033E-03	**Cpl**	3.9324
		Cpu	N/A
Cpk	3.9324		
Skew	-1.0411		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

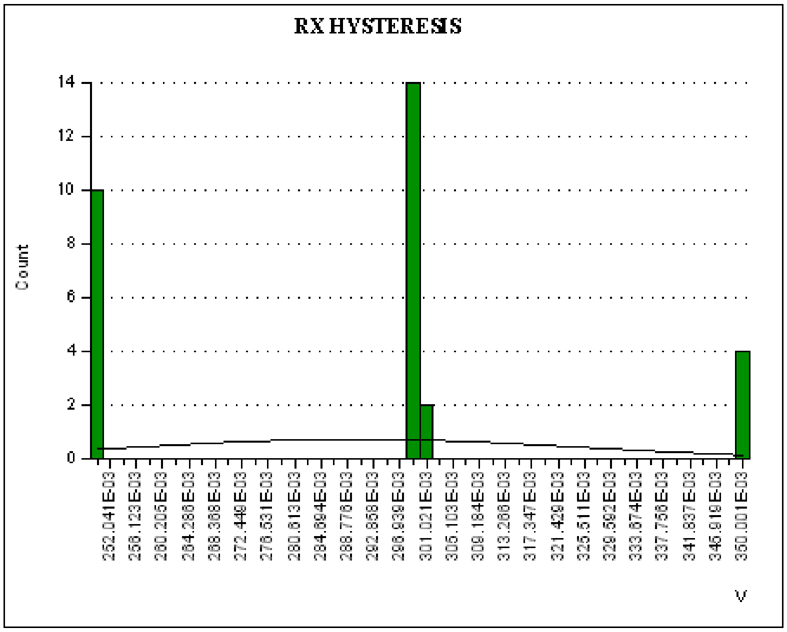
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.005, Test.Name=RX HYSTERESIS



Statistics: (V)

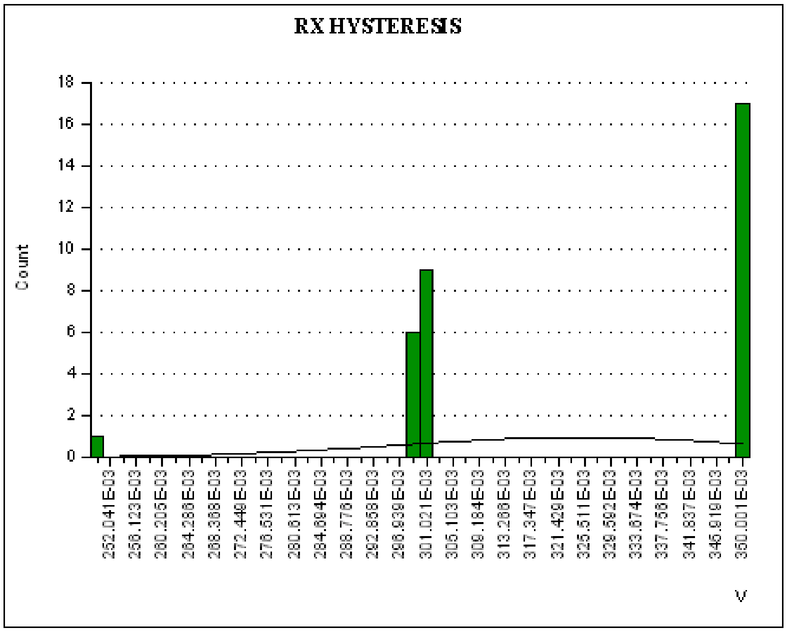
Min	250.000E-03	**Skew**	0.2419
Max	350.001E-03	**StatHigh**	N/A
Mean	290.000E-03	**StatLow**	N/A
StdDev	33.218E-03	**NWithinSpec**	N/A
25%	250.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	389.655E-03	**90%**	350.001E-03
		Range	100.000E-03
Mean-3*StdDev	190.346E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.005, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	250.000E-03	**StatLow**	N/A
Max	350.001E-03	**NWithinSpec**	N/A
Mean	324.243E-03	**NOutsideSpec**	N/A
StdDev	28.288E-03	**90%**	350.001E-03
25%	300.001E-03	**Range**	100.000E-03
Mean+3*StdDev	409.106E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	239.380E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.4885		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

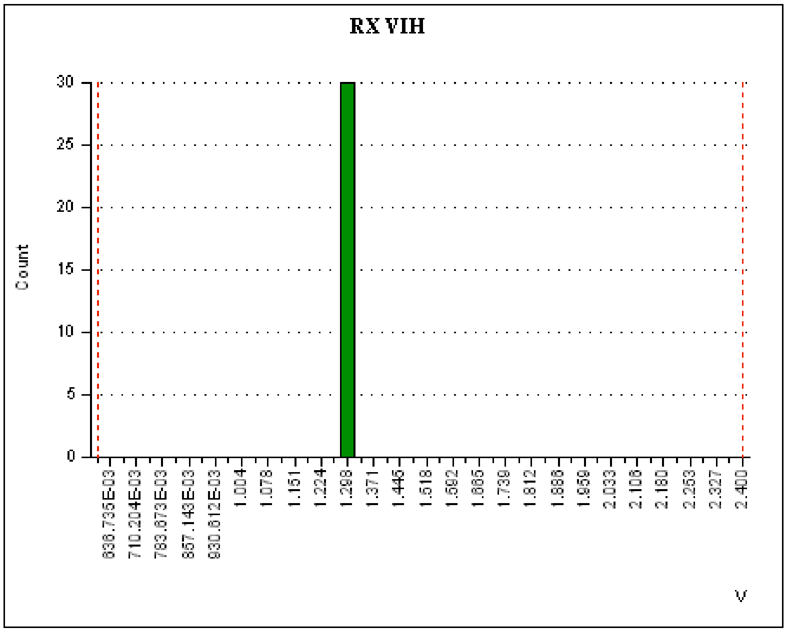
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.006, Test.Name=RX VIH



Statistics: (V)

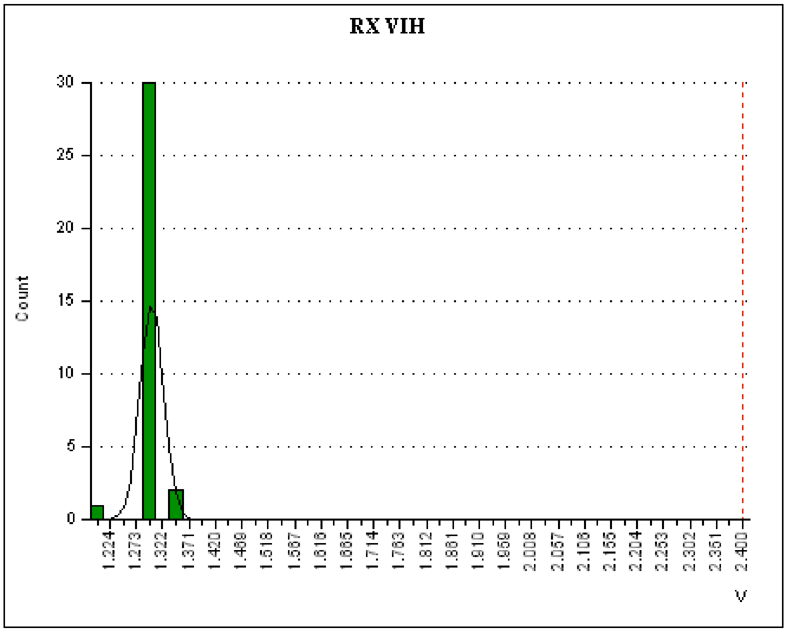
Min	1.300	**Skew**	N/A
Max	1.300	**StatHigh**	N/A
Mean	1.300	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.300	**90%**	1.300
		Range	0
Mean-3*StdDev	1.300	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.006, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.350	**NWithinSpec**	33
Mean	1.300	**NOutsideSpec**	0
StdDev	21.651E-03	**90%**	1.300
25%	1.300	**Range**	150.001E-03
Mean+3*StdDev	1.365	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.235	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-2.4584		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

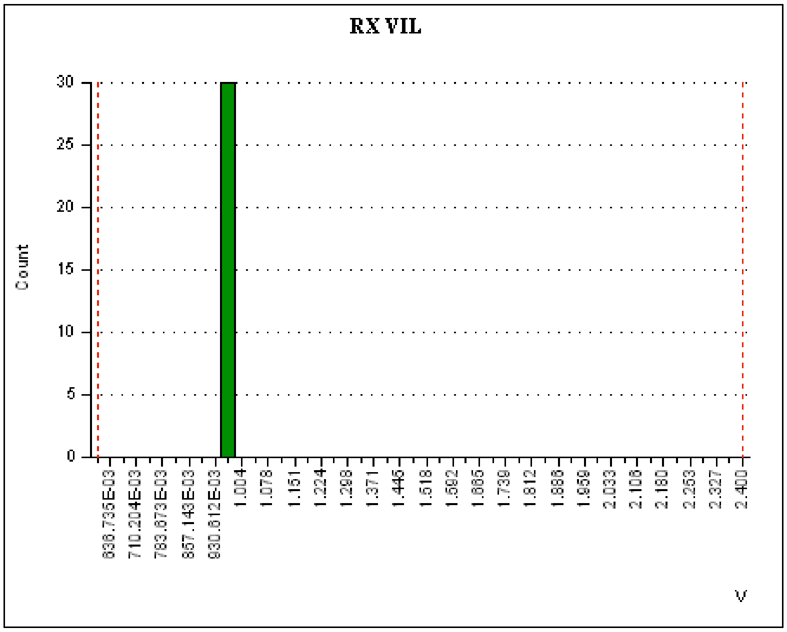
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.007, Test.Name=RX VIL



Statistics: (V)

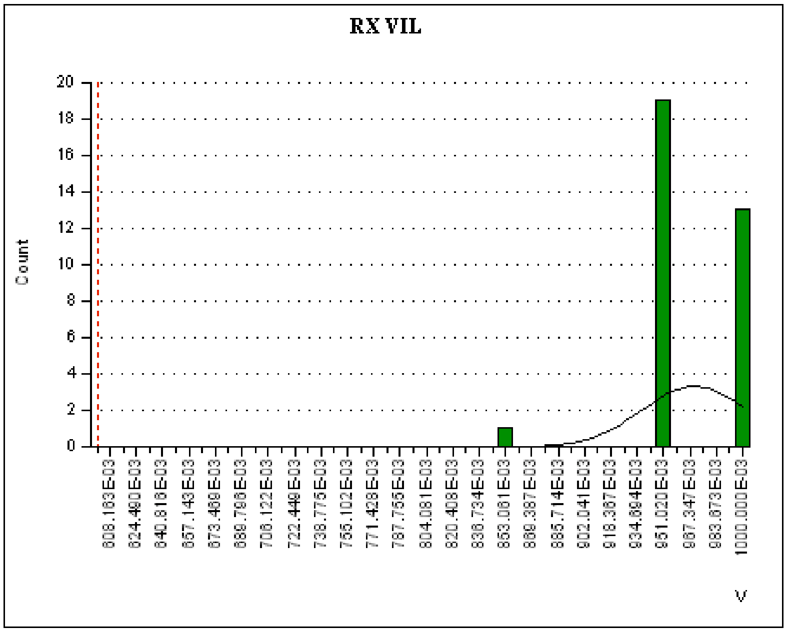
Min	950.000E-03	**Skew**	N/A
Max	950.000E-03	**StatHigh**	N/A
Mean	950.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	950.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	950.000E-03	**90%**	950.000E-03
		Range	0
Mean-3*StdDev	950.000E-03	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.007, Test.Name=RX VIL



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	33
Mean	966.666E-03	**NOutsideSpec**	0
StdDev	32.275E-03	**90%**	1000.000E-03
25%	950.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.063	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	869.842E-03	**Cpl**	3.7869
		Cpu	N/A
Cpk	3.7869		
Skew	-1.1819		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

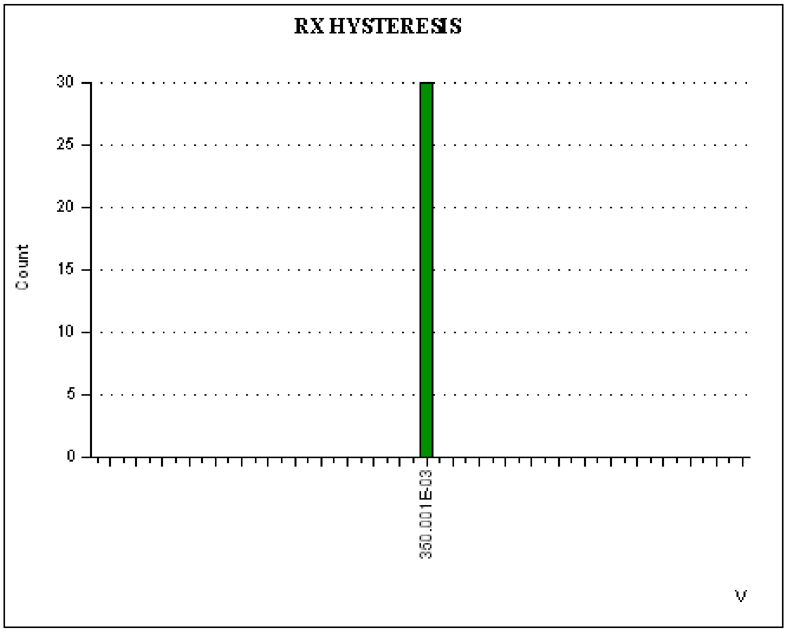
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.008, Test.Name=RX HYSTERESIS



Statistics: (V)

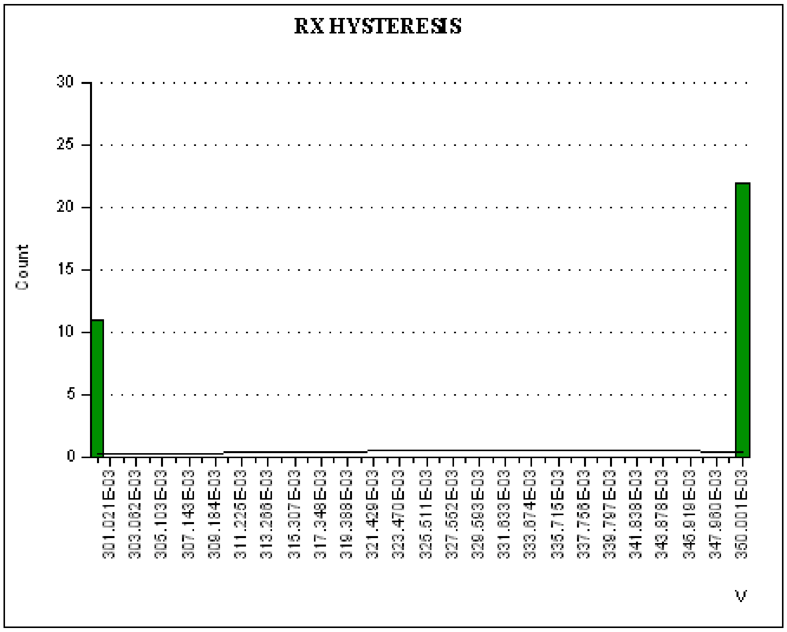
Min	350.001E-03	**Skew**	N/A
Max	350.001E-03	**StatHigh**	N/A
Mean	350.001E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	350.001E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	350.001E-03	**90%**	350.001E-03
		Range	0
Mean-3*StdDev	350.001E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	300.001E-03	**StatLow**	N/A
Max	350.001E-03	**NWithinSpec**	N/A
Mean	333.334E-03	**NOutsideSpec**	N/A
StdDev	23.936E-03	**90%**	350.001E-03
25%	300.001E-03	**Range**	50.000E-03
Mean+3*StdDev	405.141E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	261.527E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.7412		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

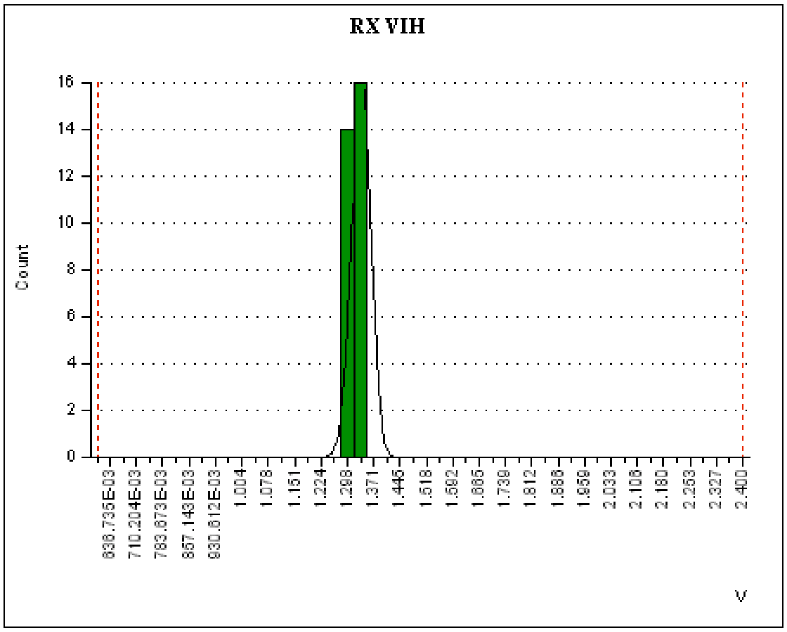
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.009, Test.Name=RX VIH



Statistics: (V)

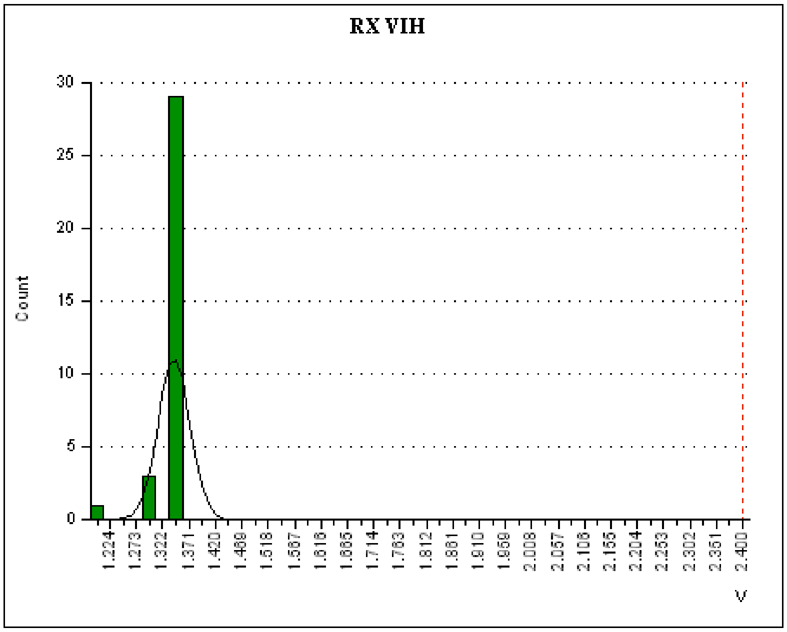
Min	1.300	**Skew**	-0.1408
Max	1.350	**StatHigh**	N/A
Mean	1.327	**StatLow**	N/A
StdDev	25.371E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.403	**90%**	1.350
Mean-3*StdDev	1.251	**Range**	50.000E-03
Cpk	>4.0000	**NOutsideSpec**	0

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.009, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.350	**NWithinSpec**	33
Mean	1.341	**NOutsideSpec**	0
StdDev	29.194E-03	**90%**	1.350
25%	1.350	**Range**	150.001E-03
Mean+3*StdDev	1.428	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.253	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-3.9862		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

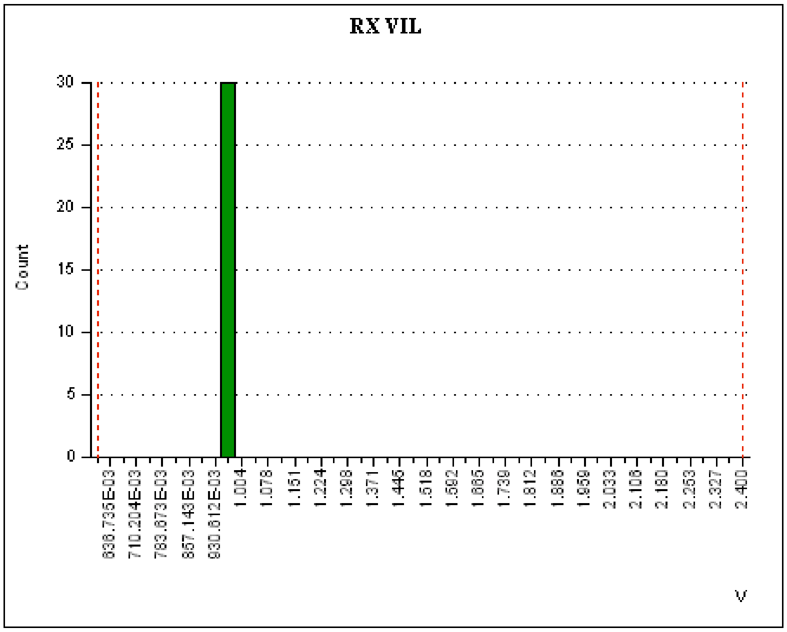
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.010, Test.Name=RX VIL



Statistics: (V)

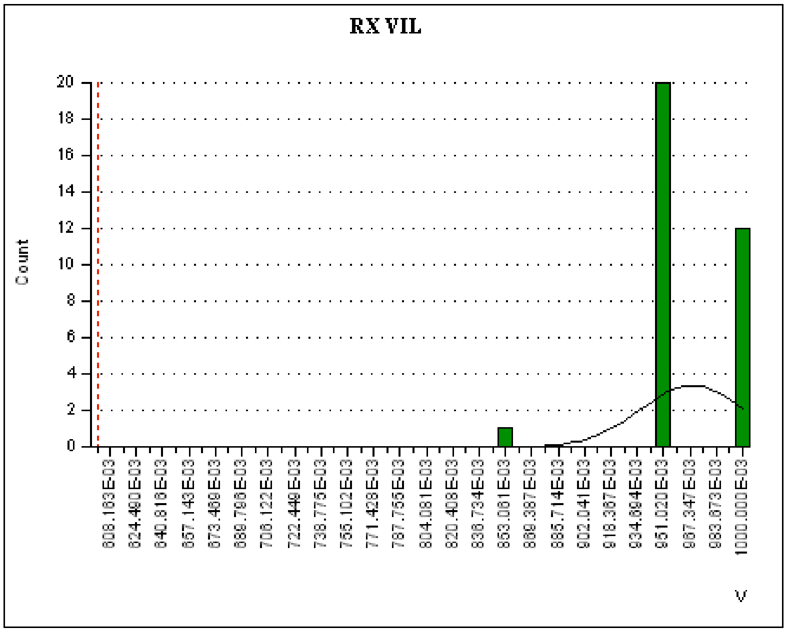
Min	950.000E-03	**Skew**	N/A
Max	950.000E-03	**StatHigh**	N/A
Mean	950.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	950.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	950.000E-03	**90%**	950.000E-03
		Range	0
Mean-3*StdDev	950.000E-03	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.010, Test.Name=RX VIL



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	33
Mean	965.151E-03	**NOutsideSpec**	0
StdDev	31.832E-03	**90%**	1000.000E-03
25%	950.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.061	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	869.656E-03	**Cpl**	3.8238
Cpk	3.8238	**Cpu**	N/A
Skew	-1.1228		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

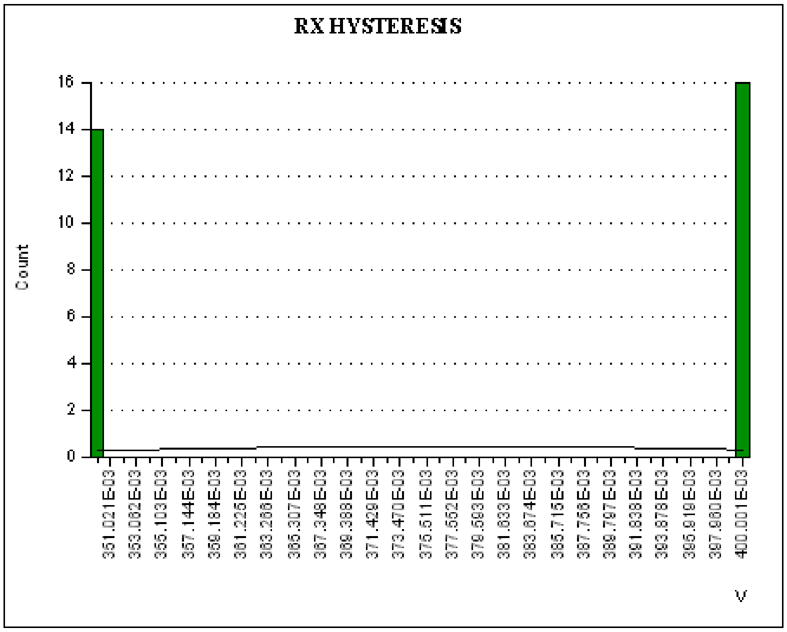
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.011, Test.Name=RX HYSTERESIS



Statistics: (V)

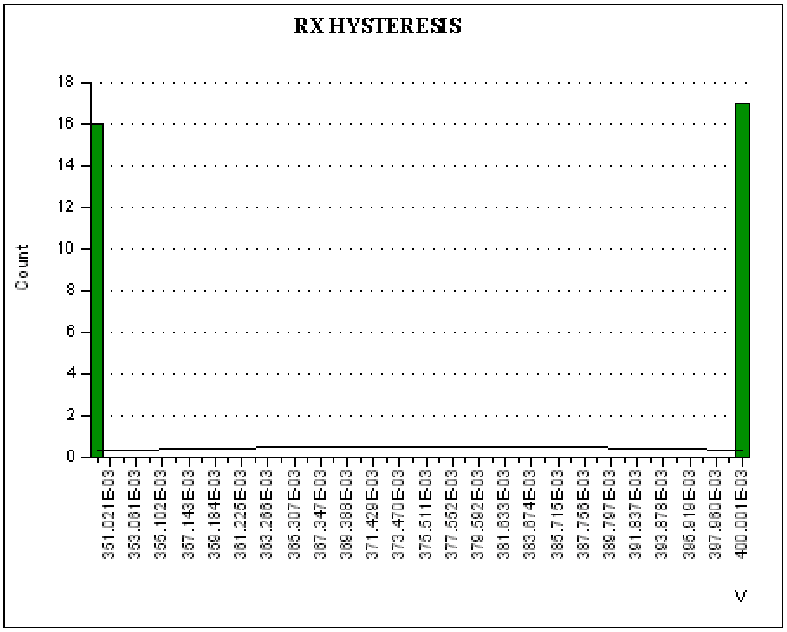
Min	350.001E-03	**Skew**	-0.1408
Max	400.001E-03	**StatHigh**	N/A
Mean	376.667E-03	**StatLow**	N/A
StdDev	25.371E-03	**NWithinSpec**	N/A
25%	350.001E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	452.780E-03	**90%**	400.001E-03
		Range	50.000E-03
Mean-3*StdDev	300.555E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.011, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	350.000E-03	**StatLow**	N/A
Max	400.001E-03	**NWithinSpec**	N/A
Mean	375.758E-03	**NOutsideSpec**	N/A
StdDev	25.376E-03	**90%**	400.001E-03
25%	350.001E-03	**Range**	50.001E-03
Mean+3*StdDev	451.886E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	299.630E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0636		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

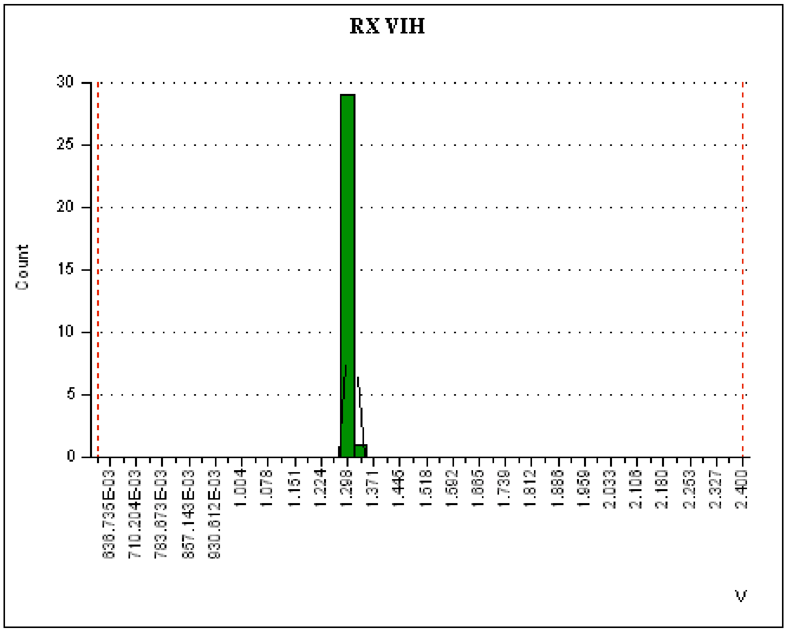
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.012, Test.Name=RX VIH



Statistics: (V)

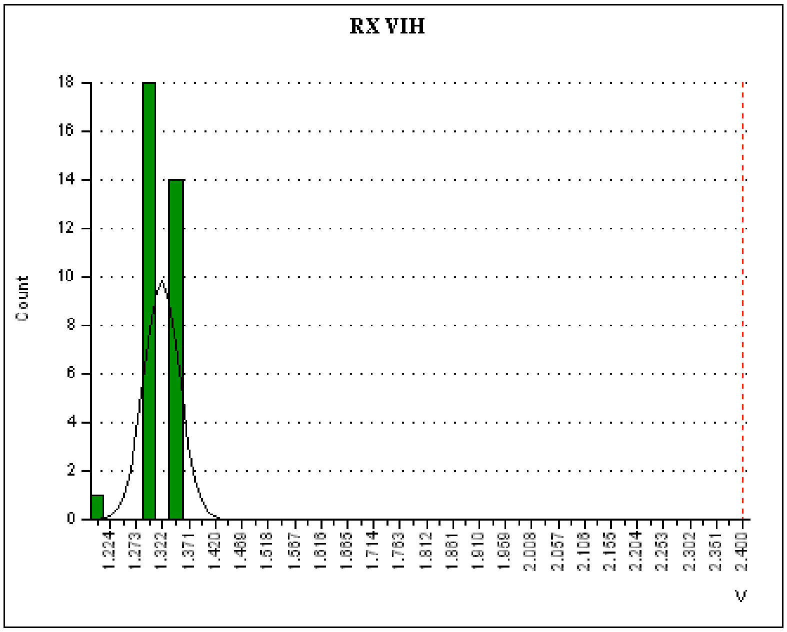
Min	1.300	**Skew**	5.4772
Max	1.350	**StatHigh**	N/A
Mean	1.302	**StatLow**	N/A
StdDev	9.129E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.329	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.274	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.012, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.350	**NWithinSpec**	33
Mean	1.318	**NOutsideSpec**	0
StdDev	32.640E-03	**90%**	1.350
25%	1.300	**Range**	150.001E-03
Mean+3*StdDev	1.416	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.220	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-1.2512		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

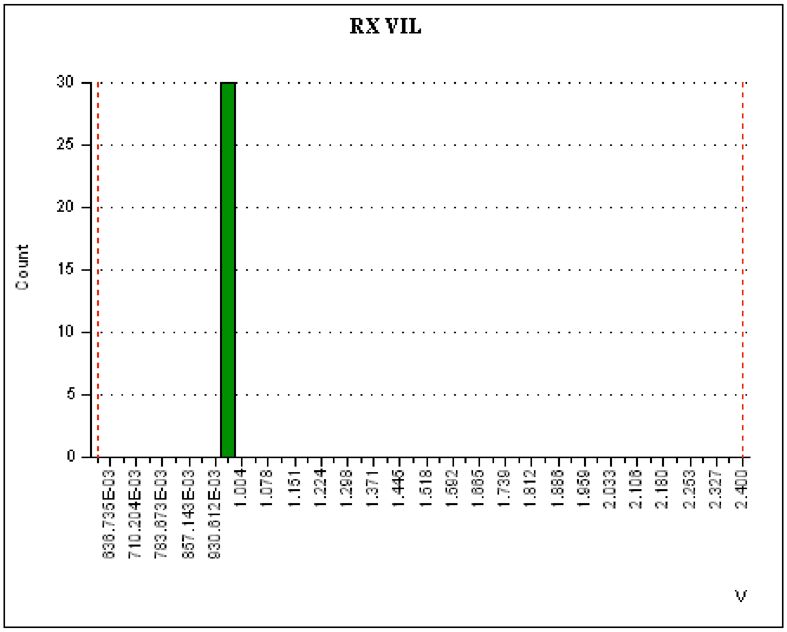
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.013, Test.Name=RX VIL



Statistics: (V)

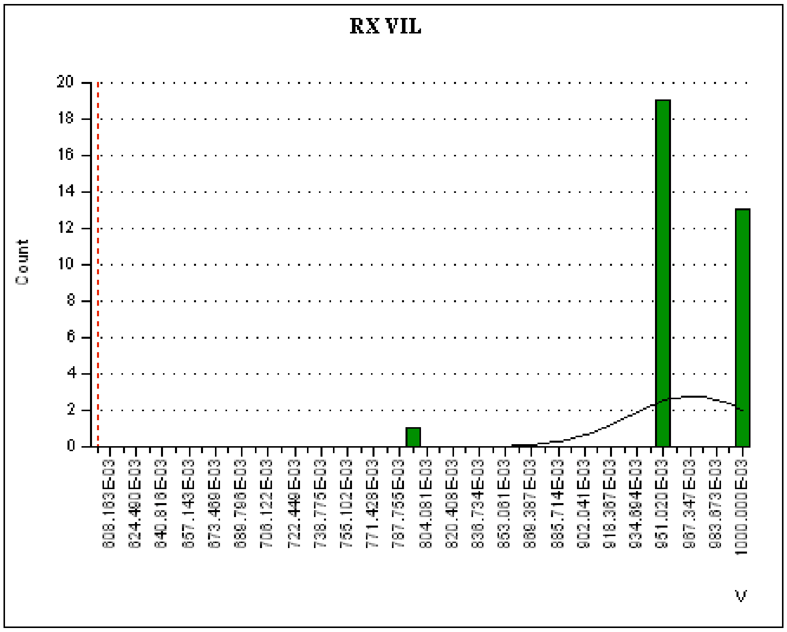
Min	950.000E-03	**Skew**	N/A
Max	950.000E-03	**StatHigh**	N/A
Mean	950.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	950.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	950.000E-03	**90%**	950.000E-03
		Range	0
Mean-3*StdDev	950.000E-03	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.013, Test.Name=RX VIL



Statistics: (V)

Min	800.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	33
Mean	965.151E-03	**NOutsideSpec**	0
StdDev	38.497E-03	**90%**	1000.000E-03
25%	950.000E-03	**Range**	200.000E-03
Mean+3*StdDev	1.081	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	849.661E-03	**Cpl**	3.1617
		Cpu	N/A
Cpk	3.1617		
Skew	-2.3442		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

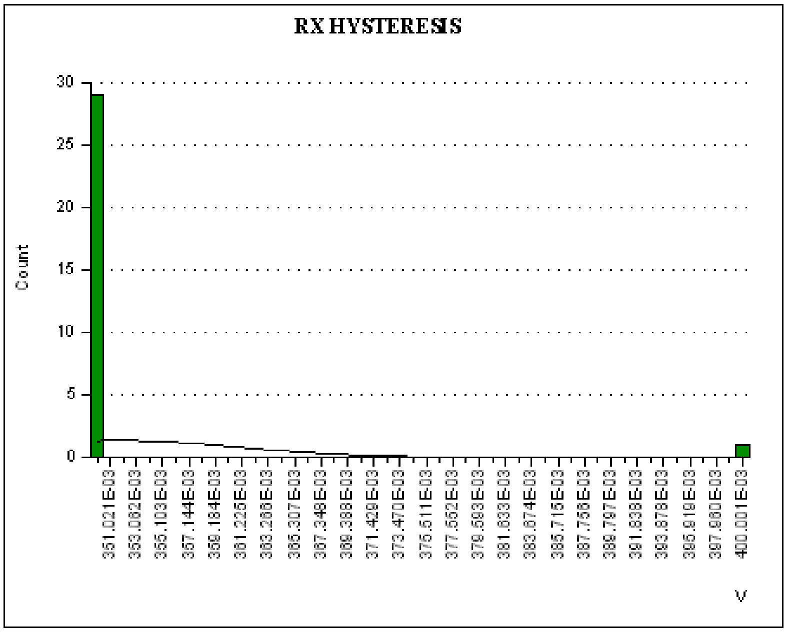
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=10.014, Test.Name=RX HYSTERESIS



Statistics: (V)

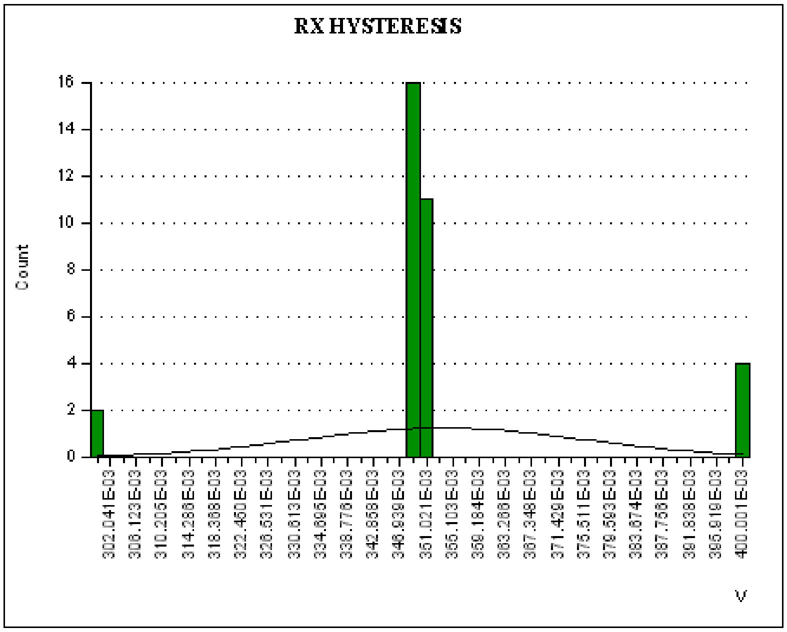
Min	350.001E-03	**Skew**	5.4772
Max	400.001E-03	**StatHigh**	N/A
Mean	351.667E-03	**StatLow**	N/A
StdDev	9.129E-03	**NWithinSpec**	N/A
25%	350.001E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	379.054E-03	**90%**	350.001E-03
		Range	50.000E-03
Mean-3*StdDev	324.281E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.014, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	300.001E-03	**StatLow**	N/A
Max	400.001E-03	**NWithinSpec**	N/A
Mean	353.031E-03	**NOutsideSpec**	N/A
StdDev	21.431E-03	**90%**	400.000E-03
25%	350.001E-03	**Range**	100.000E-03
Mean+3*StdDev	417.323E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	288.738E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3903		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

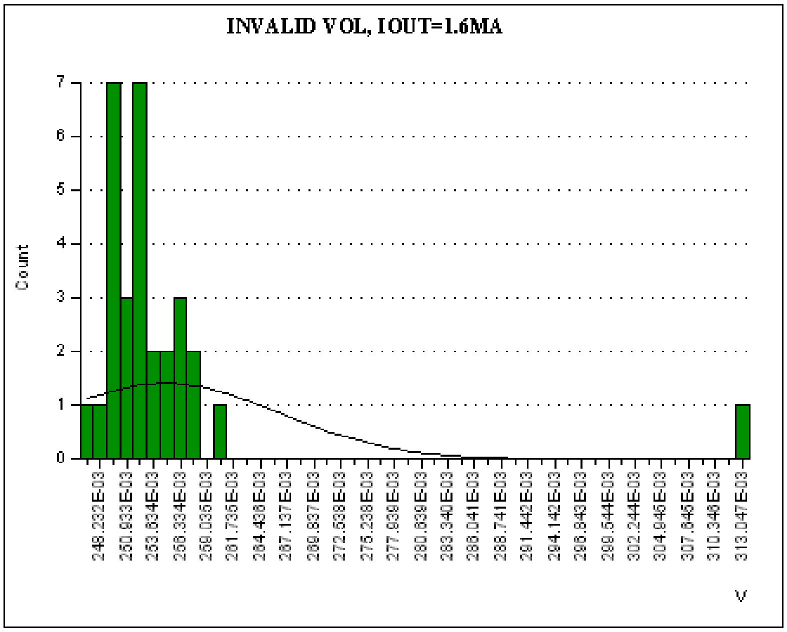
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=12.000, Test.Name=INVALID VOL, IOUT=1.6MA



Statistics: (V)

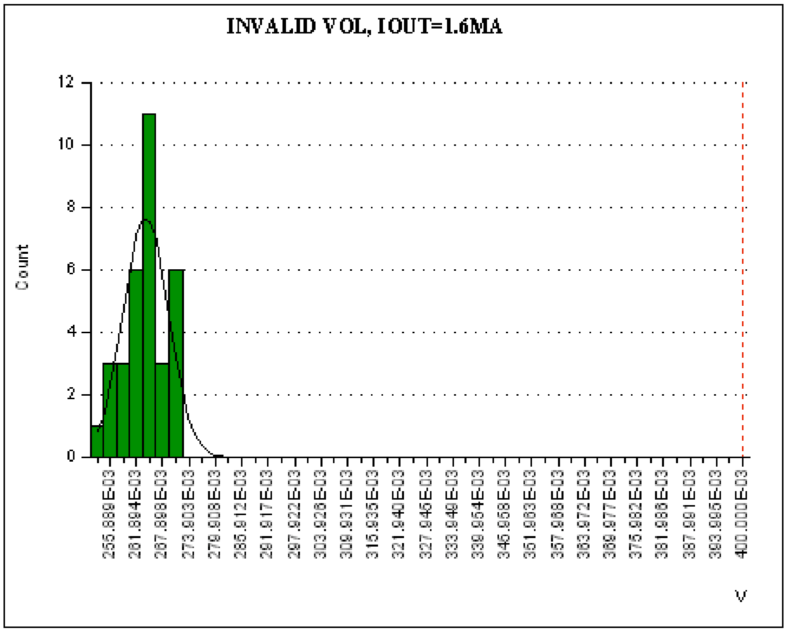
Min	246.882E-03	**Skew**	4.8408
Max	313.047E-03	**StatHigh**	N/A
Mean	254.700E-03	**StatLow**	N/A
StdDev	11.459E-03	**NWithinSpec**	N/A
25%	250.237E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	289.077E-03	**90%**	258.088E-03
		Range	66.164E-03
Mean-3*StdDev	220.322E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=12.000, Test.Name=INVALID VOL, IOUT=1.6MA



Statistics: (V)

Min	252.887E-03	**StatLow**	N/A
Max	271.728E-03	**NWithinSpec**	33
Mean	263.765E-03	**NOutsideSpec**	0
StdDev	5.137E-03	**90%**	270.819E-03
25%	260.746E-03	**Range**	18.841E-03
Mean+3*StdDev	279.176E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	248.353E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.2090		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

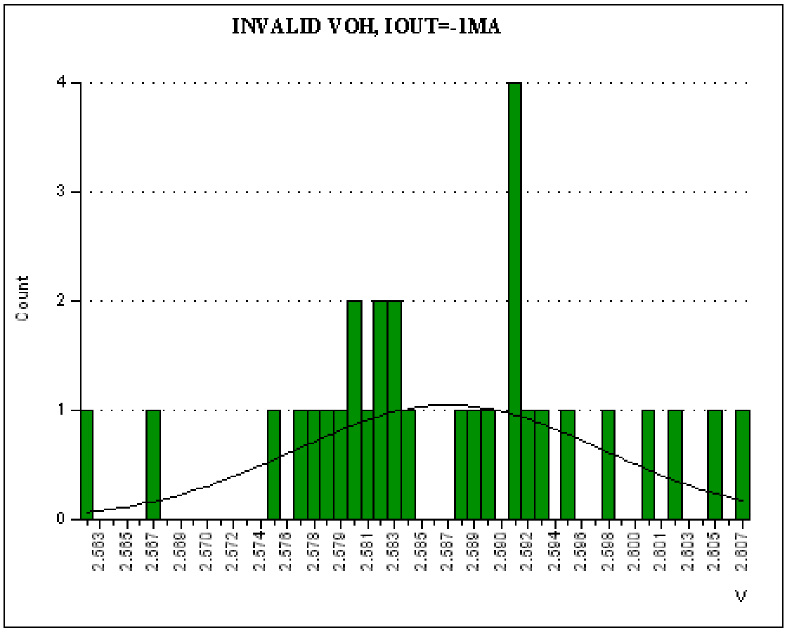
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=12.001, Test.Name=INVALID VOH, IOUT=-1MA



Statistics: (V)

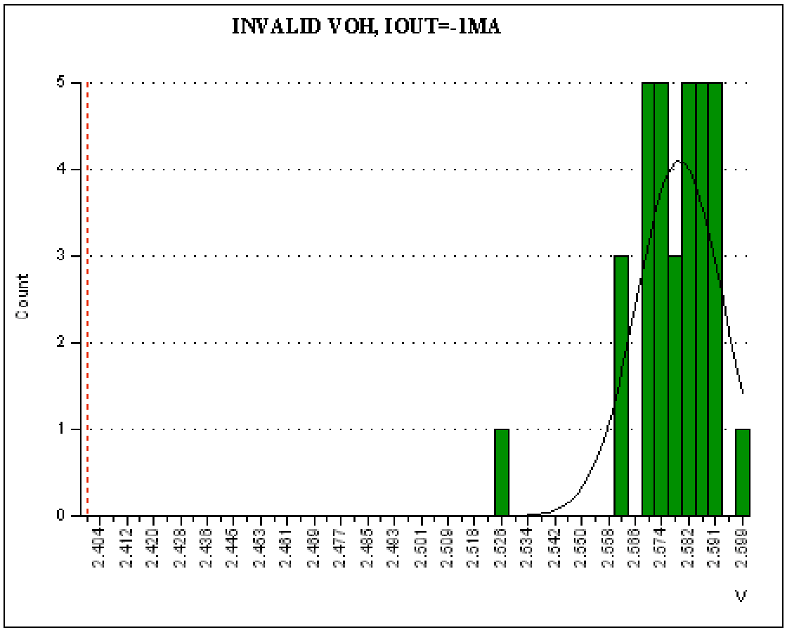
Min	2.562	**Skew**	-0.1198
Max	2.607	**StatHigh**	N/A
Mean	2.587	**StatLow**	N/A
StdDev	10.440E-03	**NWithinSpec**	N/A
25%	2.581	**NOutsideSpec**	N/A
Mean+3*StdDev	2.618	**90%**	2.601
		Range	44.859E-03
Mean-3*StdDev	2.555	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=12.001, Test.Name=INVALID VOH, IOUT=-1MA



Statistics: (V)

Min	2.526	**StatLow**	N/A
Max	2.599	**NWithinSpec**	33
Mean	2.578	**NOutsideSpec**	0
StdDev	13.018E-03	**90%**	2.590
25%	2.572	**Range**	73.011E-03
Mean+3*StdDev	2.617	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.539	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-1.9775		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

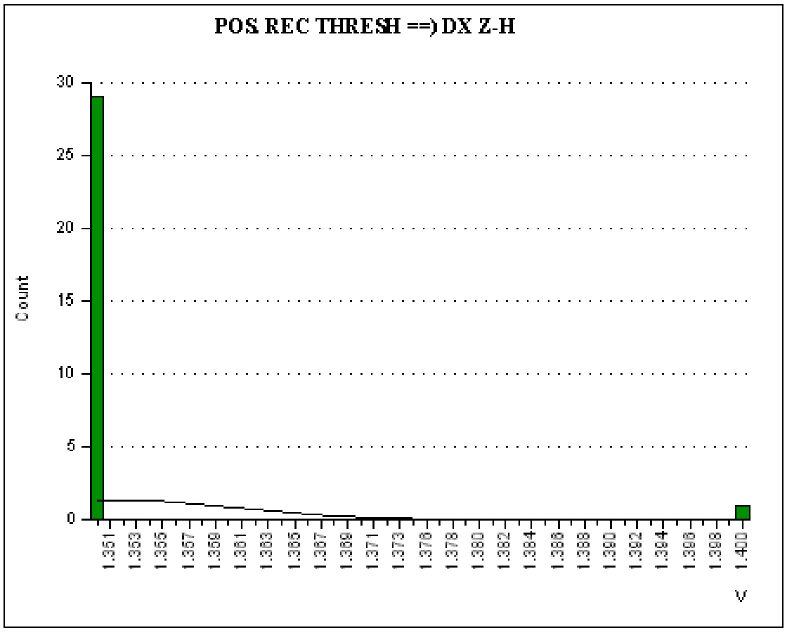
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.000, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

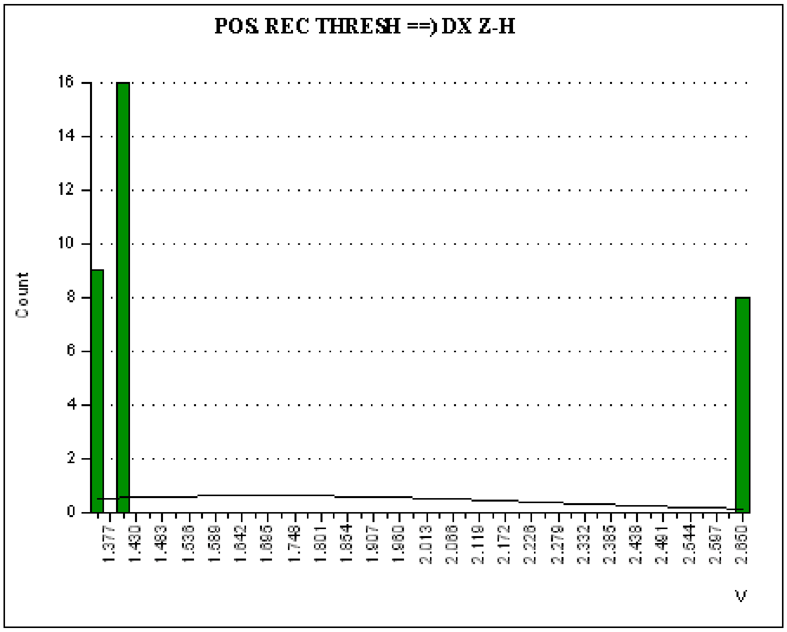
Min	1.350	**Skew**	5.4772
Max	1.400	**StatHigh**	N/A
Mean	1.352	**StatLow**	N/A
StdDev	9.129E-03	**NWithinSpec**	N/A
25%	1.350	**NOutsideSpec**	N/A
Mean+3*StdDev	1.379	**90%**	1.350
		Range	49.999E-03
Mean-3*StdDev	1.324	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.000, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	2.650	**NWithinSpec**	N/A
Mean	1.689	**NOutsideSpec**	N/A
StdDev	552.234E-03	**90%**	2.650
25%	1.350	**Range**	1.300
Mean+3*StdDev	3.346	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	32.693E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.2546		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

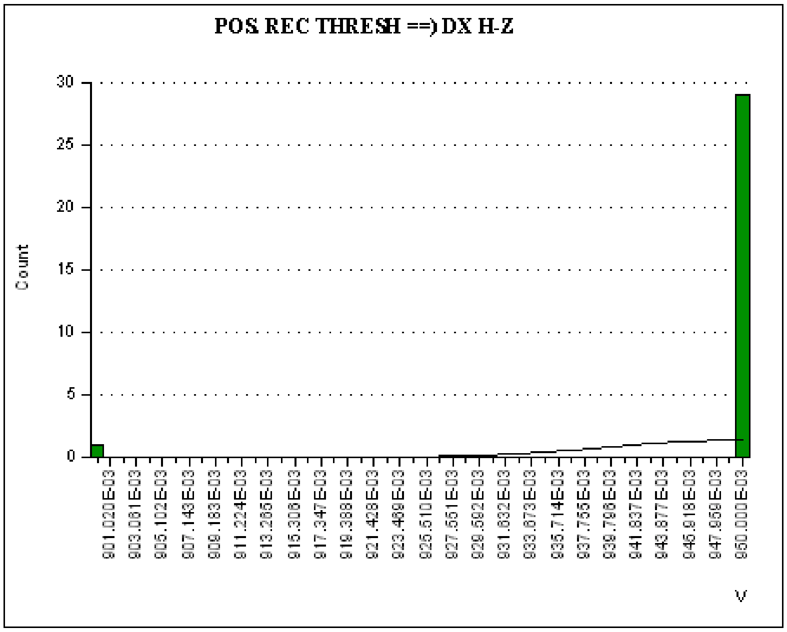
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.001, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

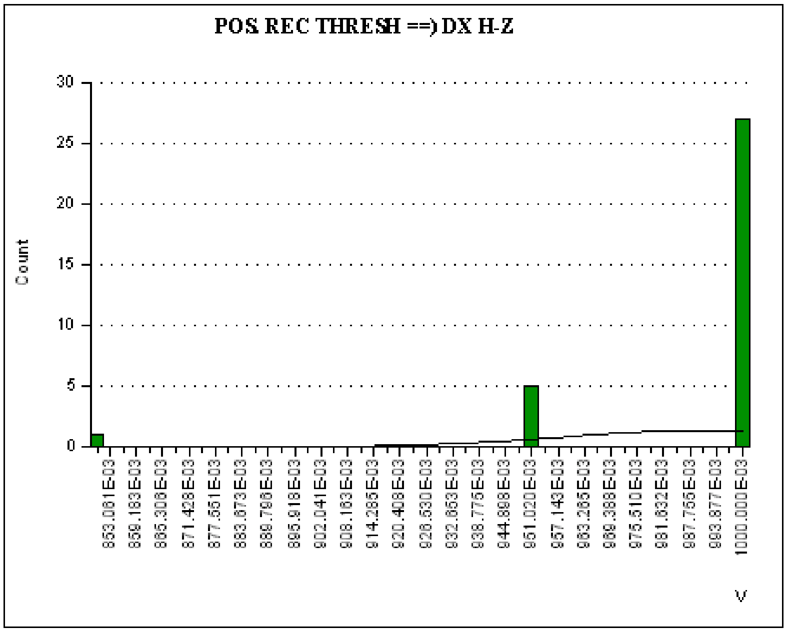
Min	900.000E-03	**Skew**	-5.4772
Max	950.000E-03	**StatHigh**	N/A
Mean	948.333E-03	**StatLow**	N/A
StdDev	9.129E-03	**NWithinSpec**	N/A
25%	950.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	975.719E-03	**90%**	950.000E-03
		Range	50.000E-03
Mean-3*StdDev	920.947E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.001, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	N/A
Mean	987.879E-03	**NOutsideSpec**	N/A
StdDev	30.696E-03	**90%**	1000.000E-03
25%	1000.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.080	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	895.791E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-3.2720		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

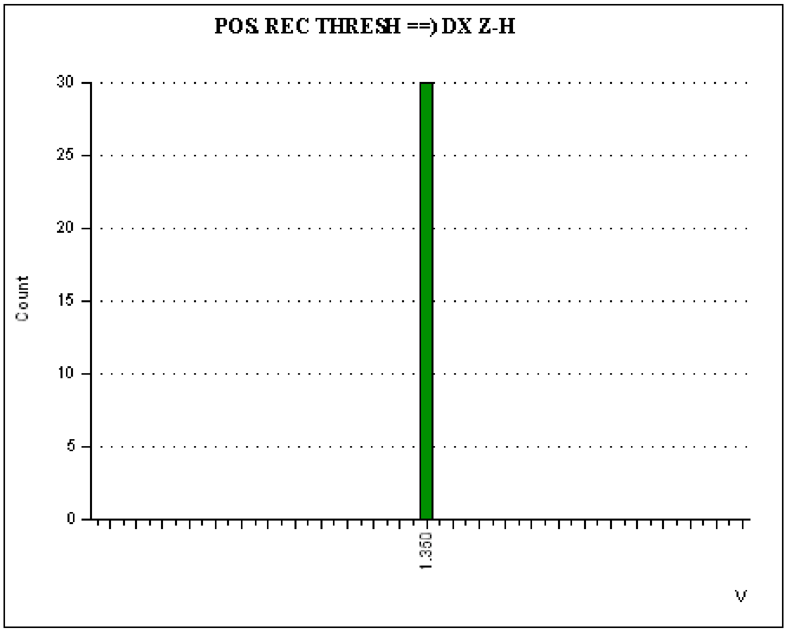
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.002, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

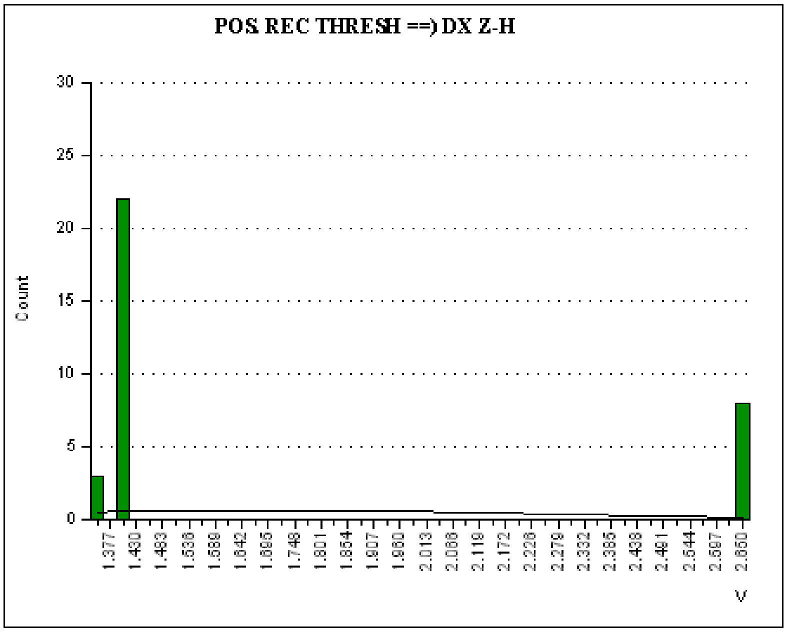
Min	1.350	**Skew**	N/A
Max	1.350	**StatHigh**	N/A
Mean	1.350	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	1.350	**NOutsideSpec**	N/A
Mean+3*StdDev	1.350	**90%**	1.350
		Range	0
Mean-3*StdDev	1.350	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.002, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	2.650	**NWithinSpec**	N/A
Mean	1.698	**NOutsideSpec**	N/A
StdDev	546.792E-03	**90%**	2.650
25%	1.400	**Range**	1.300
Mean+3*StdDev	3.339	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	58.107E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.2575		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

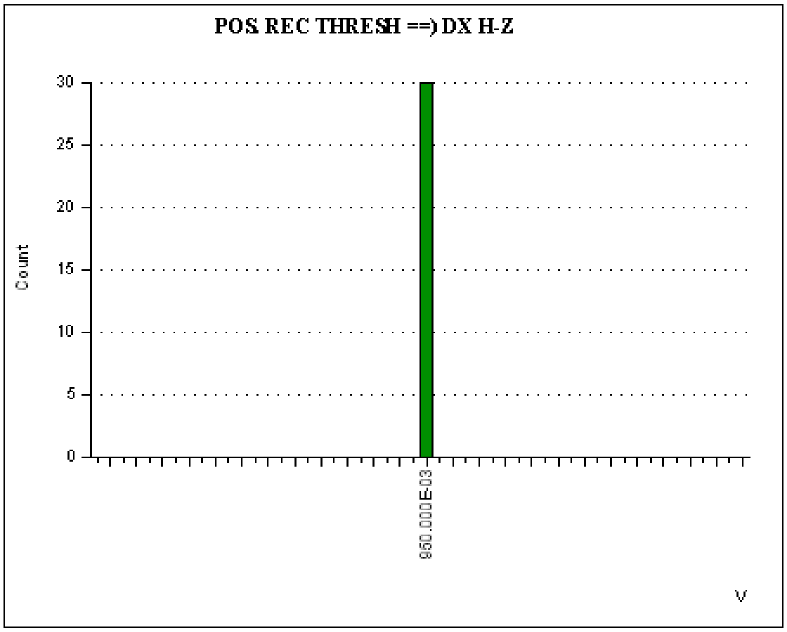
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.003, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

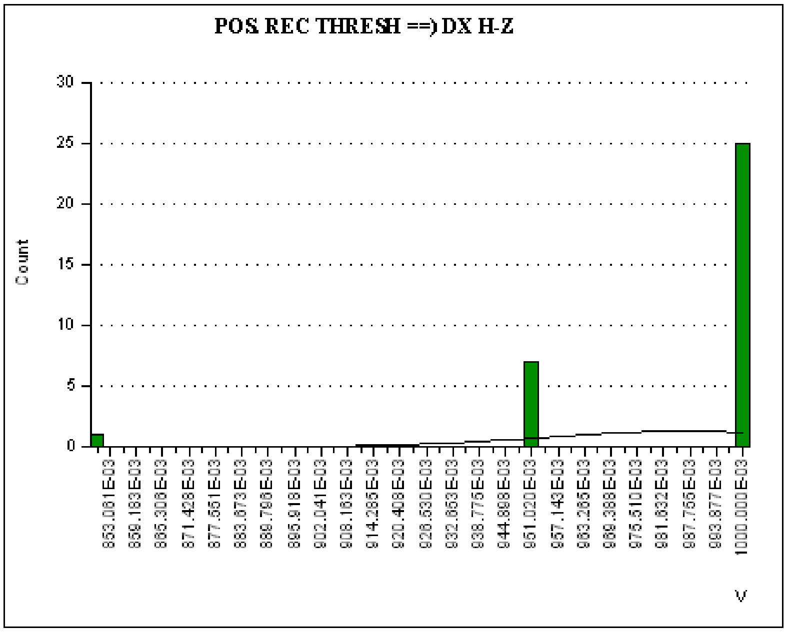
Min	950.000E-03	**Skew**	N/A
Max	950.000E-03	**StatHigh**	N/A
Mean	950.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	950.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	950.000E-03	**90%**	950.000E-03
		Range	0
Mean-3*StdDev	950.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.003, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	N/A
Mean	984.848E-03	**NOutsideSpec**	N/A
StdDev	31.832E-03	**90%**	1000.000E-03
25%	1000.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.080	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	889.353E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-2.7449		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

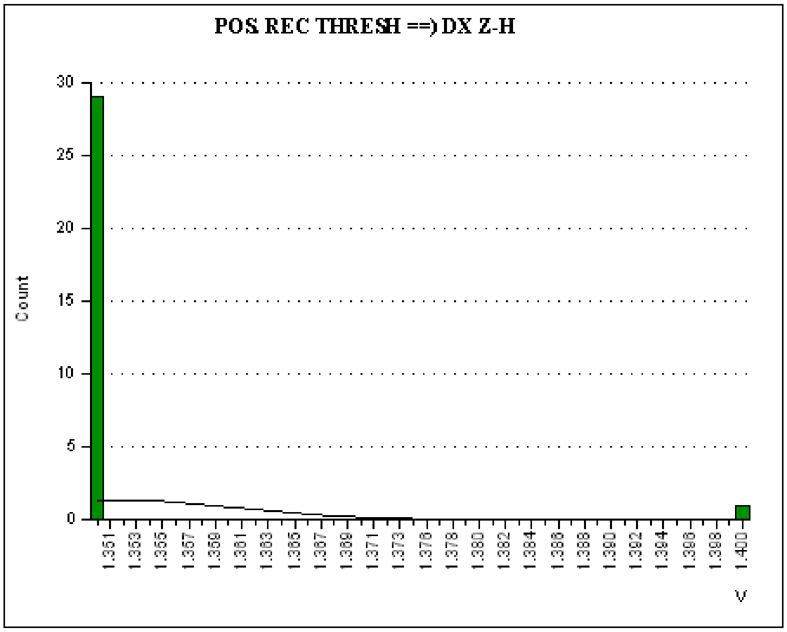
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.004, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

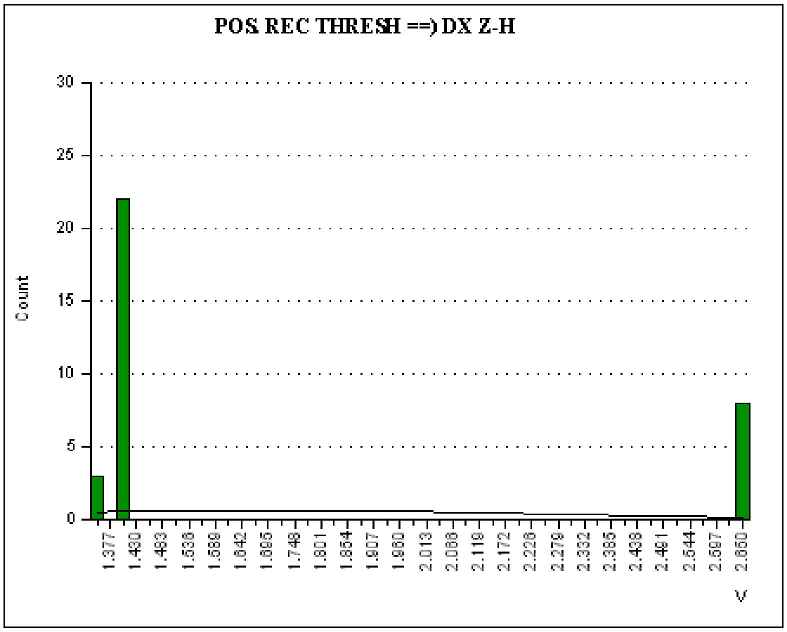
Min	1.350	**Skew**	5.4772
Max	1.400	**StatHigh**	N/A
Mean	1.352	**StatLow**	N/A
StdDev	9.129E-03	**NWithinSpec**	N/A
25%	1.350	**NOutsideSpec**	N/A
Mean+3*StdDev	1.379	**90%**	1.350
		Range	49.999E-03
Mean-3*StdDev	1.324	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.004, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	2.650	**NWithinSpec**	N/A
Mean	1.698	**NOutsideSpec**	N/A
StdDev	546.792E-03	**90%**	2.650
25%	1.400	**Range**	1.300
Mean+3*StdDev	3.339	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	58.107E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.2575		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

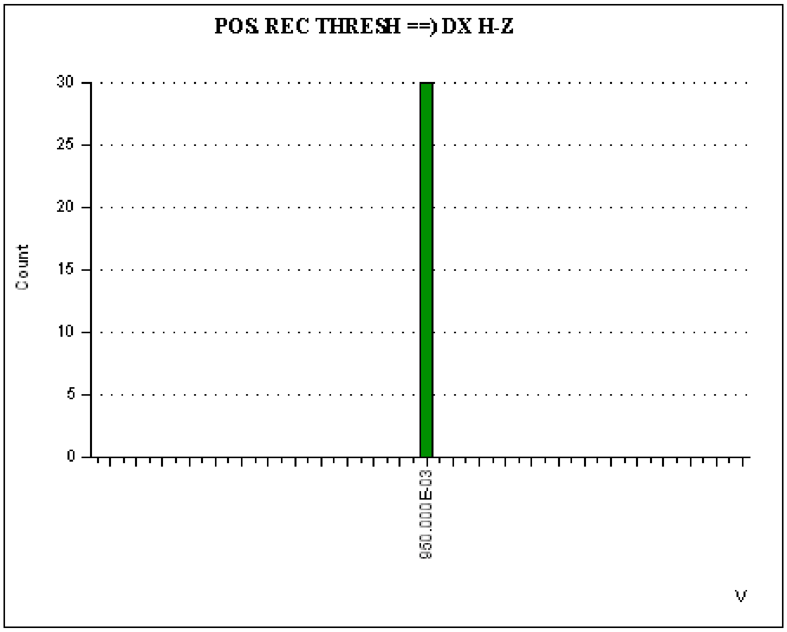
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.005, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

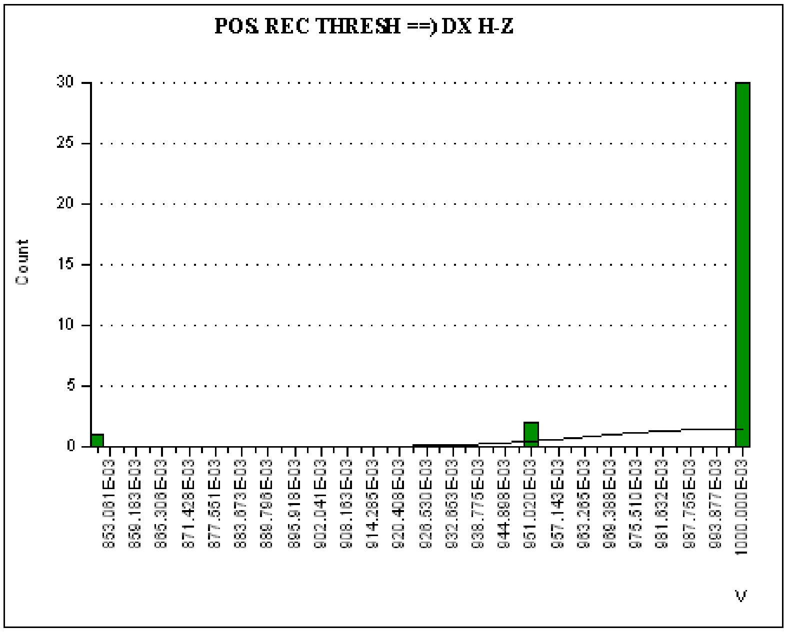
Min	950.000E-03	**Skew**	N/A
Max	950.000E-03	**StatHigh**	N/A
Mean	950.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	950.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	950.000E-03	**90%**	950.000E-03
		Range	0
Mean-3*StdDev	950.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.005, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	N/A
Mean	992.424E-03	**NOutsideSpec**	N/A
StdDev	28.288E-03	**90%**	1000.000E-03
25%	1000.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.077	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	907.561E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-4.4511		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

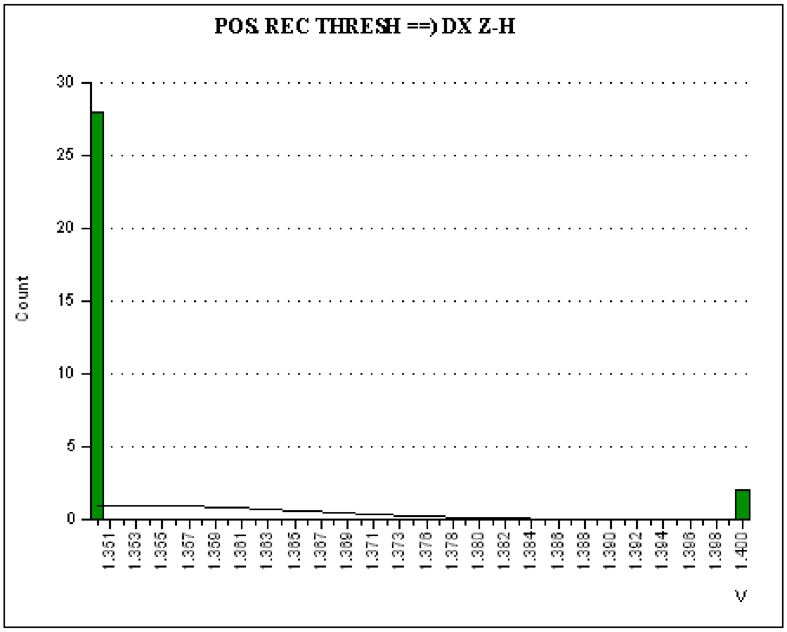
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.006, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

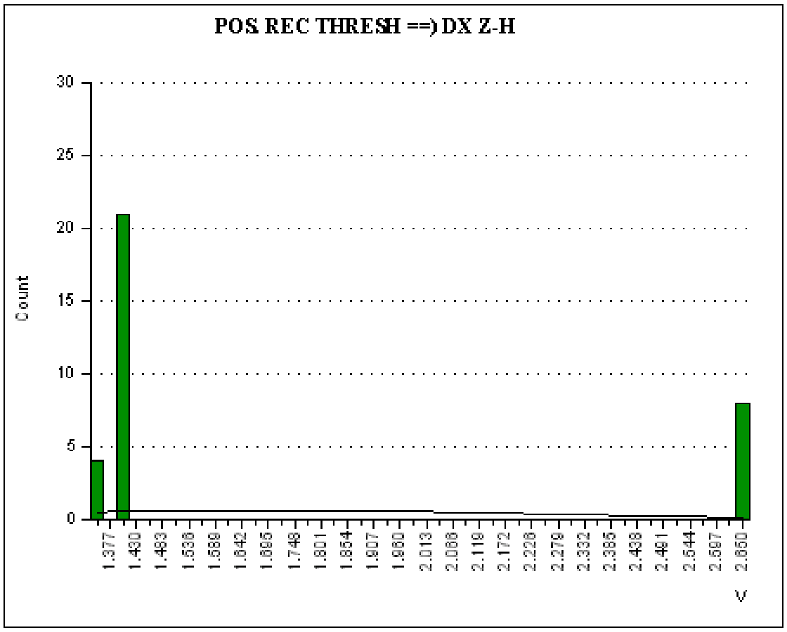
Min	1.350	**Skew**	3.6600
Max	1.400	**StatHigh**	N/A
Mean	1.353	**StatLow**	N/A
StdDev	12.685E-03	**NWithinSpec**	N/A
25%	1.350	**NOutsideSpec**	N/A
Mean+3*StdDev	1.391	**90%**	1.350
		Range	49.999E-03
Mean-3*StdDev	1.315	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.006, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	2.650	**NWithinSpec**	N/A
Mean	1.697	**NOutsideSpec**	N/A
StdDev	547.714E-03	**90%**	2.650
25%	1.400	**Range**	1.300
Mean+3*StdDev	3.340	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	53.828E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.2568		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

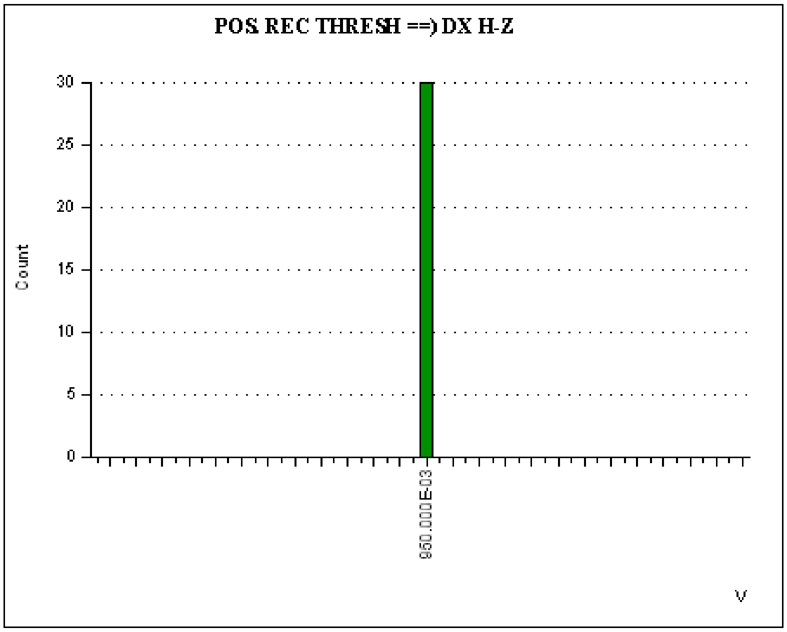
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.007, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

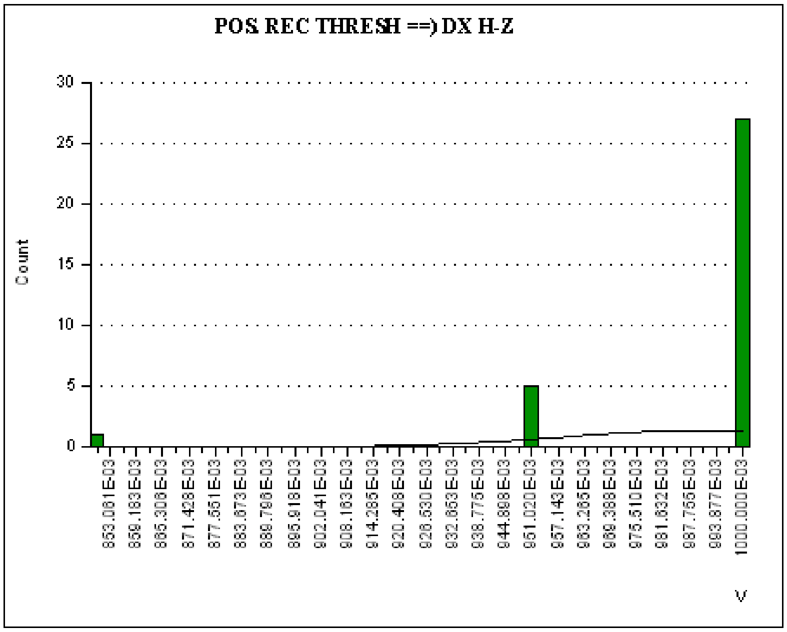
Min	950.000E-03	**Skew**	N/A
Max	950.000E-03	**StatHigh**	N/A
Mean	950.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	950.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	950.000E-03	**90%**	950.000E-03
		Range	0
Mean-3*StdDev	950.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.007, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	N/A
Mean	987.879E-03	**NOutsideSpec**	N/A
StdDev	30.696E-03	**90%**	1000.000E-03
25%	1000.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.080	**NOutsideSpec** **Cp**	N/A N/A
Mean-3*StdDev	895.791E-03	**Cpl** **Cpu**	N/A N/A
Cpk	N/A		
Skew	-3.2720		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

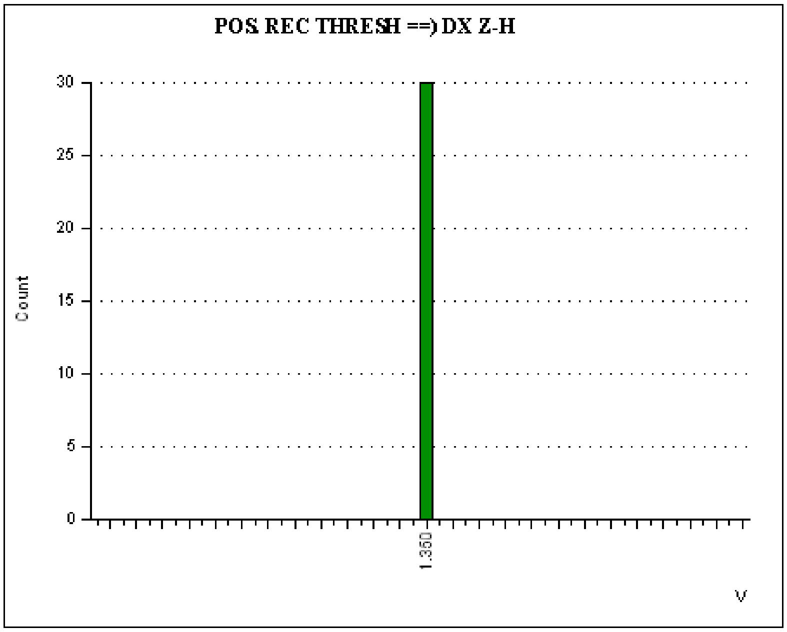
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.008, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

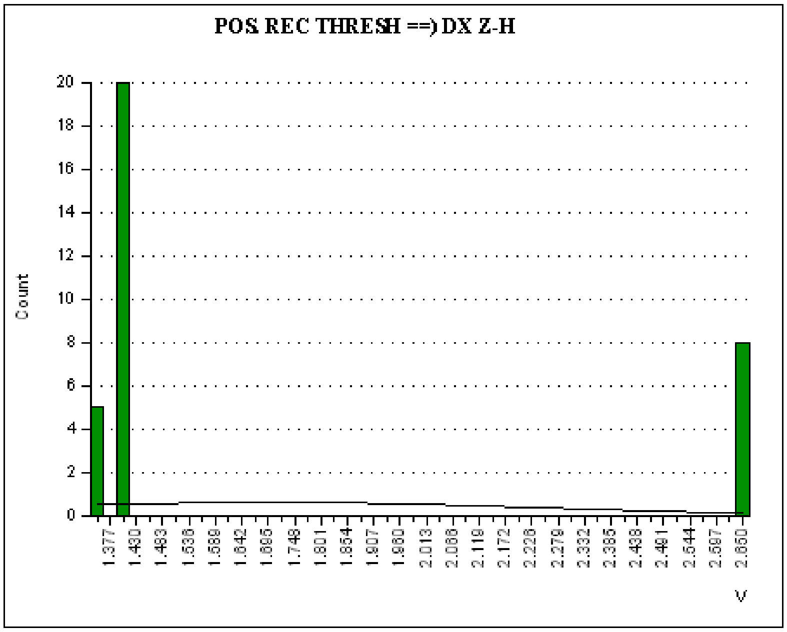
Min	1.350	**Skew**	N/A
Max	1.350	**StatHigh**	N/A
Mean	1.350	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	1.350	**NOutsideSpec**	N/A
Mean+3*StdDev	1.350	**90%**	1.350
		Range	0
Mean-3*StdDev	1.350	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.008, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	2.650	**NWithinSpec**	N/A
Mean	1.695	**NOutsideSpec**	N/A
StdDev	548.629E-03	**90%**	2.650
25%	1.400	**Range**	1.300
Mean+3*StdDev	3.341	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	49.566E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.2562		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

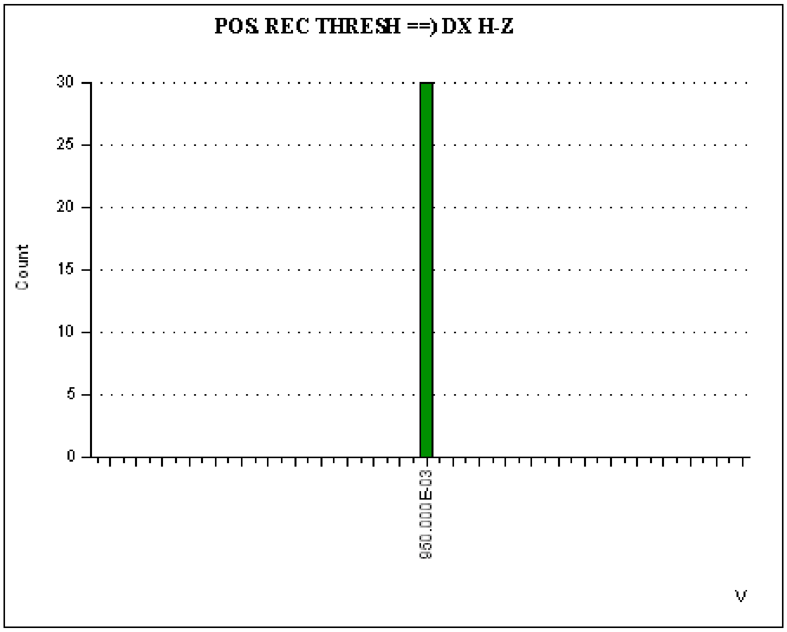
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.009, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

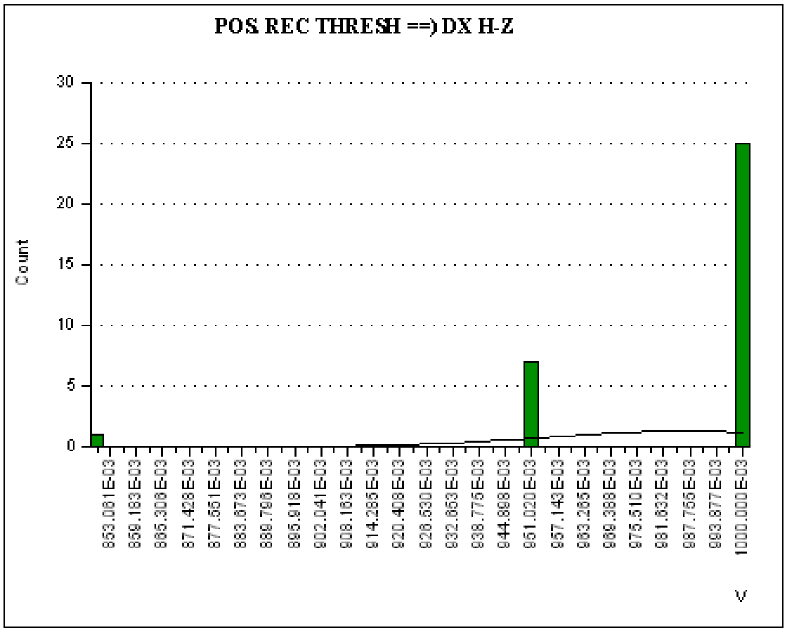
Min	950.000E-03	**Skew**	N/A
Max	950.000E-03	**StatHigh**	N/A
Mean	950.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	950.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	950.000E-03	**90%**	950.000E-03
		Range	0
Mean-3*StdDev	950.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.009, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	850.000E-03	**StatLow**	N/A
Max	1000.000E-03	**NWithinSpec**	N/A
Mean	984.848E-03	**NOutsideSpec**	N/A
StdDev	31.832E-03	**90%**	1000.000E-03
25%	1000.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.080	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	889.353E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-2.7449		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

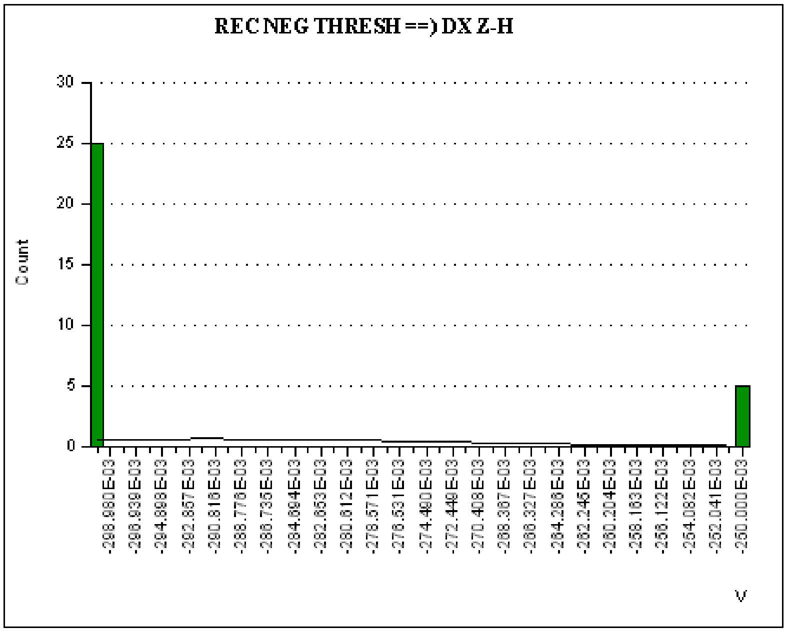
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.010, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

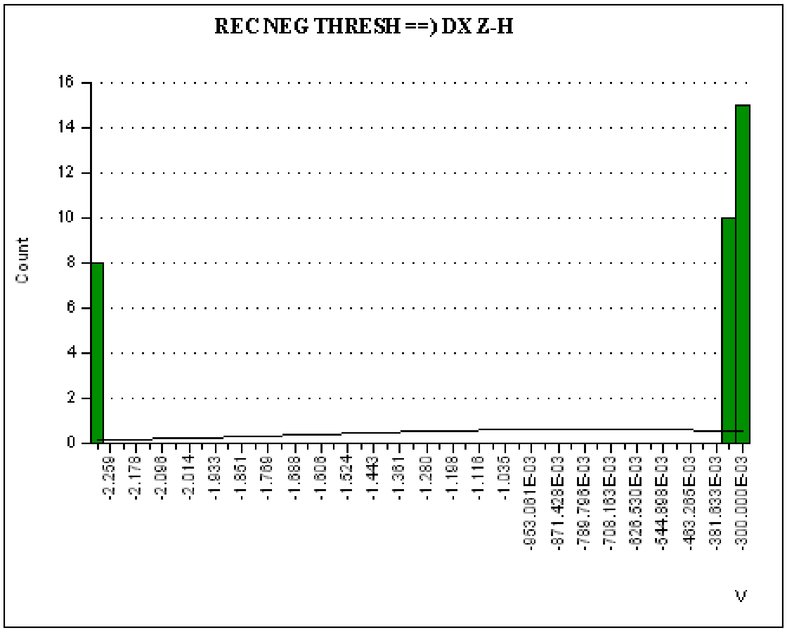
Min	-300.000E-03	**Skew**	1.8844
Max	-250.000E-03	**StatHigh**	N/A
Mean	-291.667E-03	**StatLow**	N/A
StdDev	18.952E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-234.809E-03	**90%**	-250.000E-03
		Range	50.000E-03
Mean-3*StdDev	-348.524E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.010, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-2.300	**StatLow**	N/A
Max	-300.000E-03	**NWithinSpec**	N/A
Mean	-800.000E-03	**NOutsideSpec**	N/A
StdDev	861.956E-03	**90%**	-300.000E-03
25%	-350.000E-03	**Range**	2.000
Mean+3*StdDev	1.786	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-3.386	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-1.2578		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

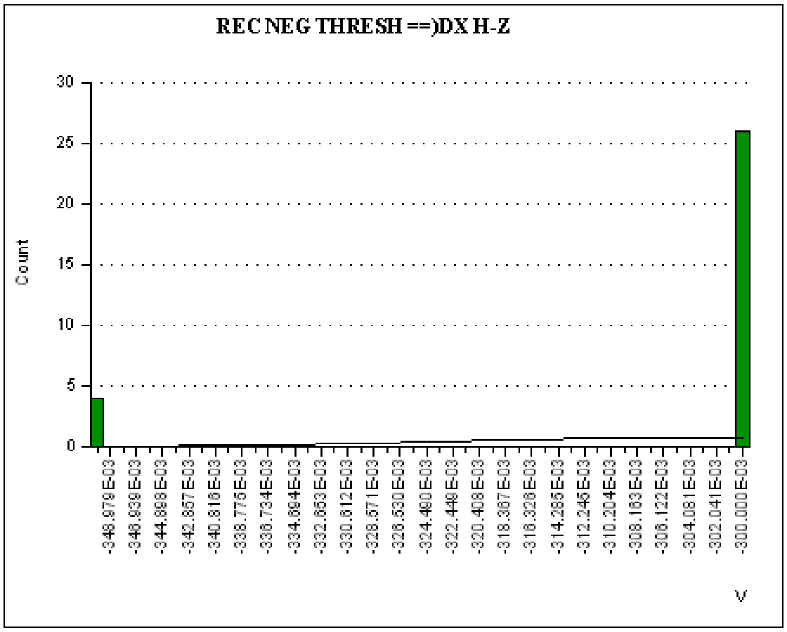
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.011, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

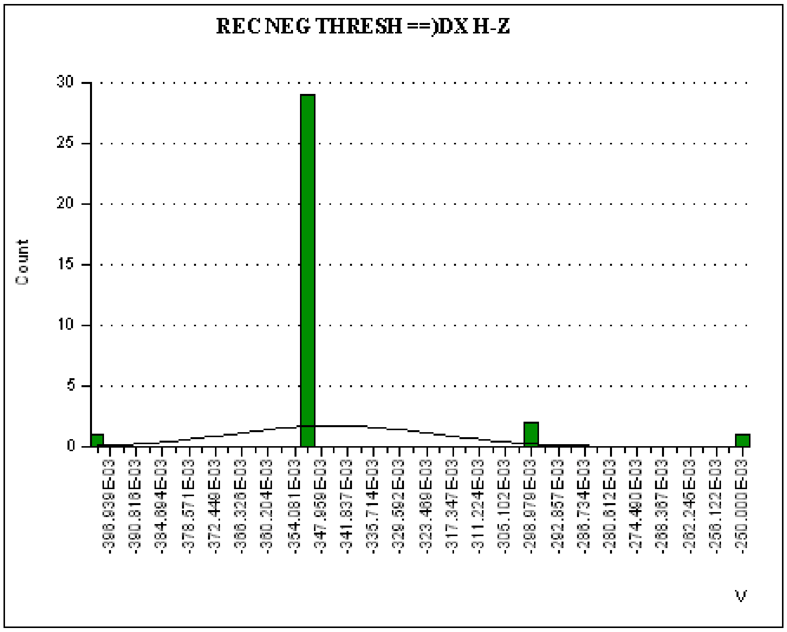
Min	-350.000E-03	**Skew**	-2.2725
Max	-300.000E-03	**StatHigh**	N/A
Mean	-306.666E-03	**StatLow**	N/A
StdDev	17.287E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-254.805E-03	**90%**	-300.000E-03
		Range	50.000E-03
Mean-3*StdDev	-358.528E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.011, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-400.000E-03	**StatLow**	N/A
Max	-250.000E-03	**NWithinSpec**	N/A
Mean	-345.454E-03	**NOutsideSpec**	N/A
StdDev	22.925E-03	**90%**	-350.000E-03
25%	-350.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-276.678E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-414.230E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.4643		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

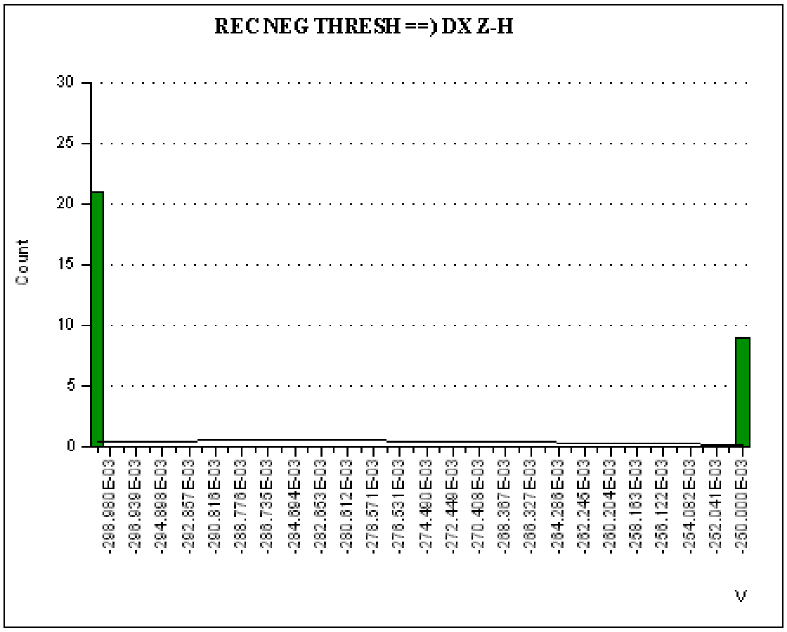
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.012, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

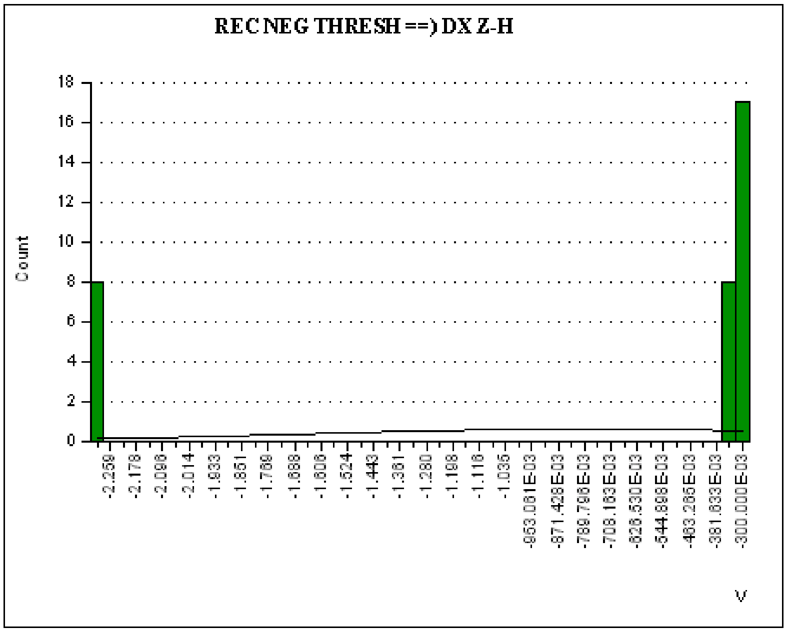
Min	-300.000E-03	**Skew**	0.9195
Max	-250.000E-03	**StatHigh**	N/A
Mean	-285.000E-03	**StatLow**	N/A
StdDev	23.305E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-215.086E-03	**90%**	-250.000E-03
		Range	50.000E-03
Mean-3*StdDev	-354.914E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.012, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-2.300	**StatLow**	N/A
Max	-300.000E-03	**NWithinSpec**	N/A
Mean	-796.970E-03	**NOutsideSpec**	N/A
StdDev	863.671E-03	**90%**	-300.000E-03
25%	-350.000E-03	**Range**	2.000
Mean+3*StdDev	1.794	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-3.388	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-1.2580		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

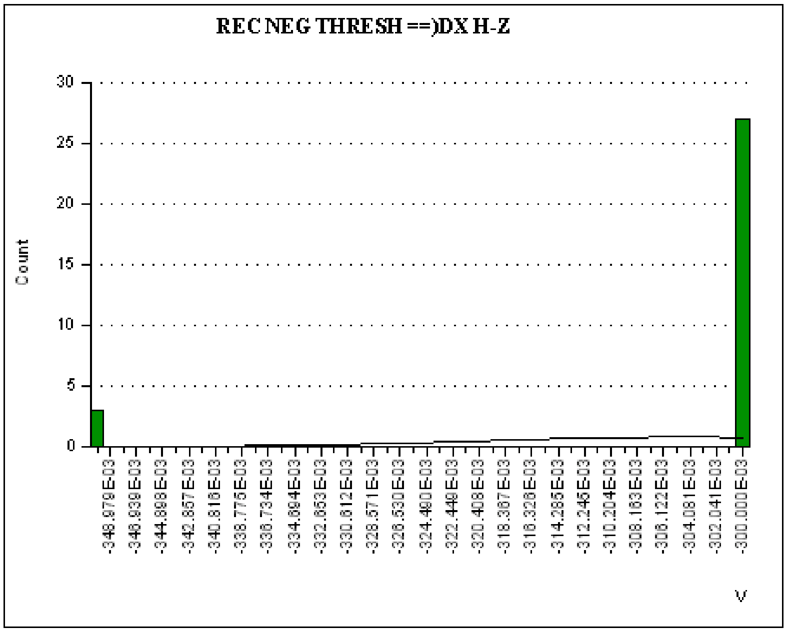
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.013, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

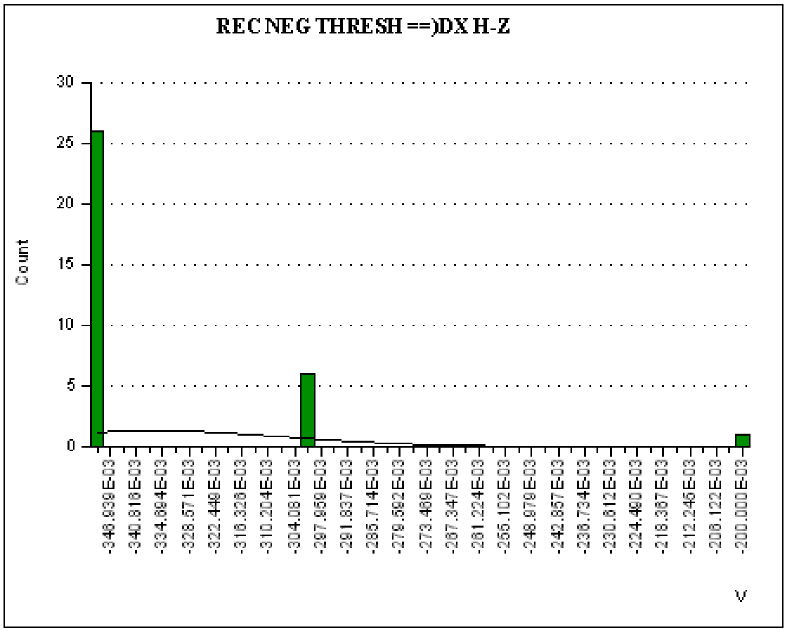
Min	-350.000E-03	**Skew**	-2.8091
Max	-300.000E-03	**StatHigh**	N/A
Mean	-305.000E-03	**StatLow**	N/A
StdDev	15.256E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-259.230E-03	**90%**	-300.000E-03
		Range	50.000E-03
Mean-3*StdDev	-350.769E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.013, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-350.000E-03	**StatLow**	N/A
Max	-200.000E-03	**NWithinSpec**	N/A
Mean	-336.363E-03	**NOutsideSpec**	N/A
StdDev	31.307E-03	**90%**	-300.000E-03
25%	-350.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-242.443E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-430.284E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.9904		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

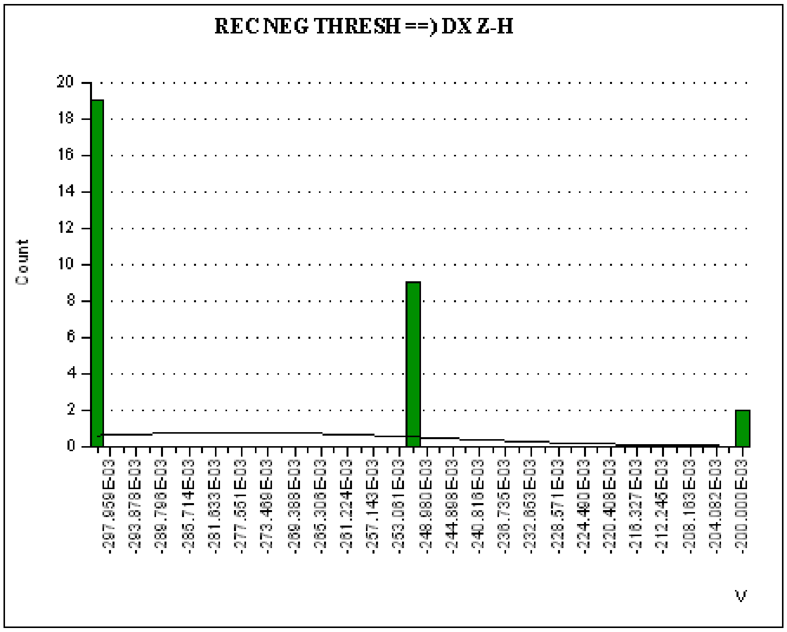
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.014, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

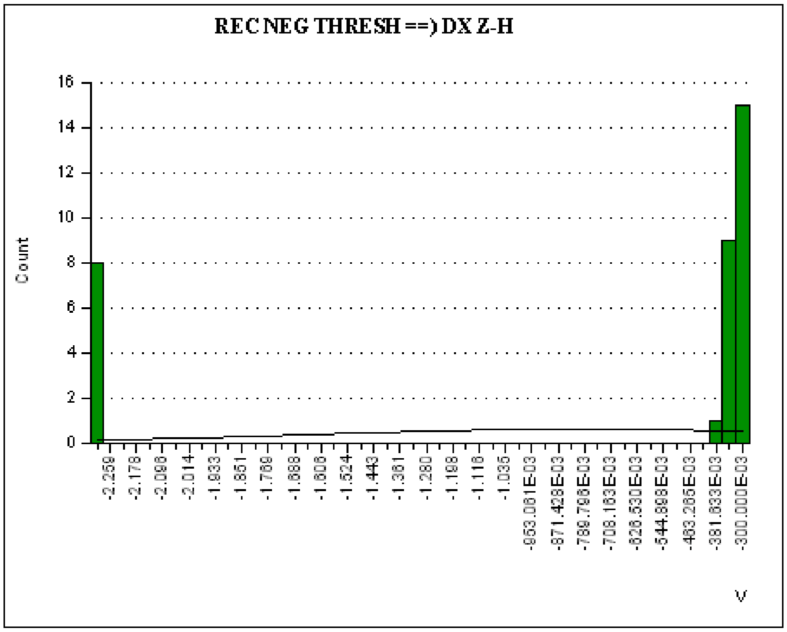
Min	-300.000E-03	**Skew**	1.1717
Max	-200.000E-03	**StatHigh**	N/A
Mean	-278.333E-03	**StatLow**	N/A
StdDev	31.303E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-184.424E-03	**90%**	-250.000E-03
		Range	100.000E-03
Mean-3*StdDev	-372.243E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.014, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-2.300	**StatLow**	N/A
Max	-300.000E-03	**NWithinSpec**	N/A
Mean	-801.515E-03	**NOutsideSpec**	N/A
StdDev	861.184E-03	**90%**	-300.000E-03
25%	-400.000E-03	**Range**	2.000
Mean+3*StdDev	1.782	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-3.385	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.2570		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

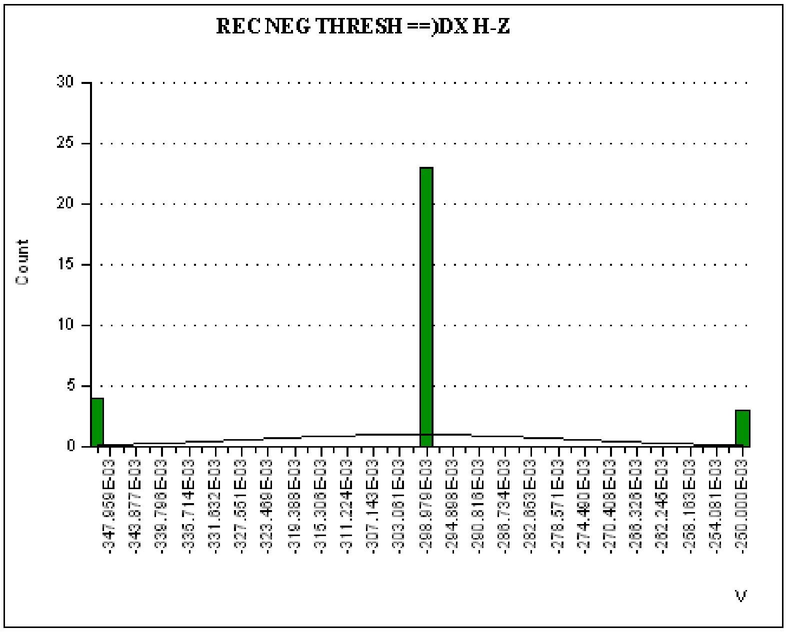
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.015, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

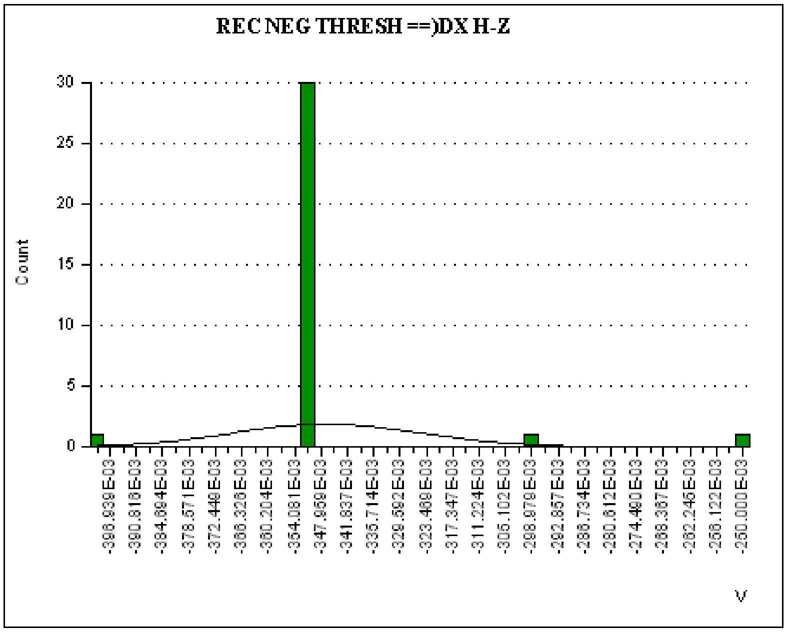
Min	-350.000E-03	**Skew**	-0.0948
Max	-250.000E-03	**StatHigh**	N/A
Mean	-301.666E-03	**StatLow**	N/A
StdDev	24.507E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-228.147E-03	**90%**	-275.000E-03
		Range	100.000E-03
Mean-3*StdDev	-375.186E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.015, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-400.000E-03	**StatLow**	N/A
Max	-250.000E-03	**NWithinSpec**	N/A
Mean	-346.969E-03	**NOutsideSpec**	N/A
StdDev	21.431E-03	**90%**	-350.000E-03
25%	-350.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-282.677E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-411.262E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.9251		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

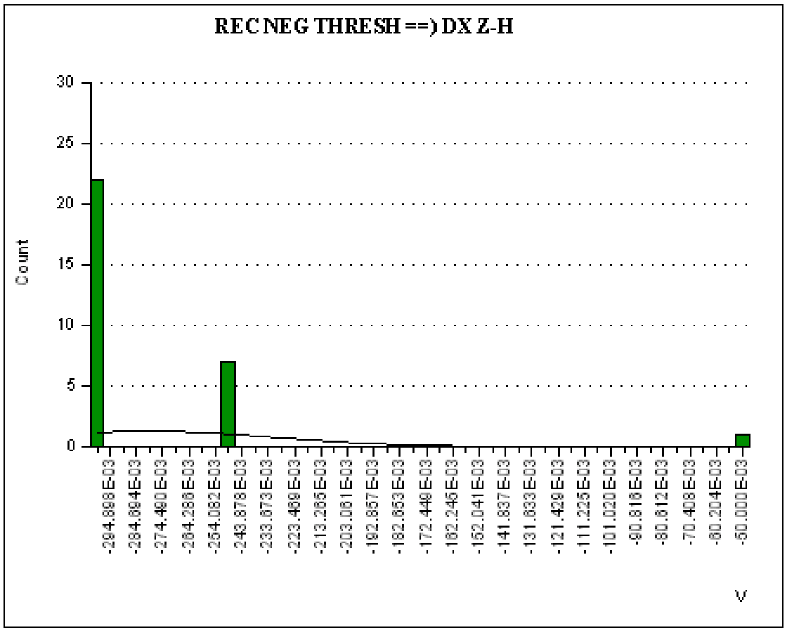
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.016, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

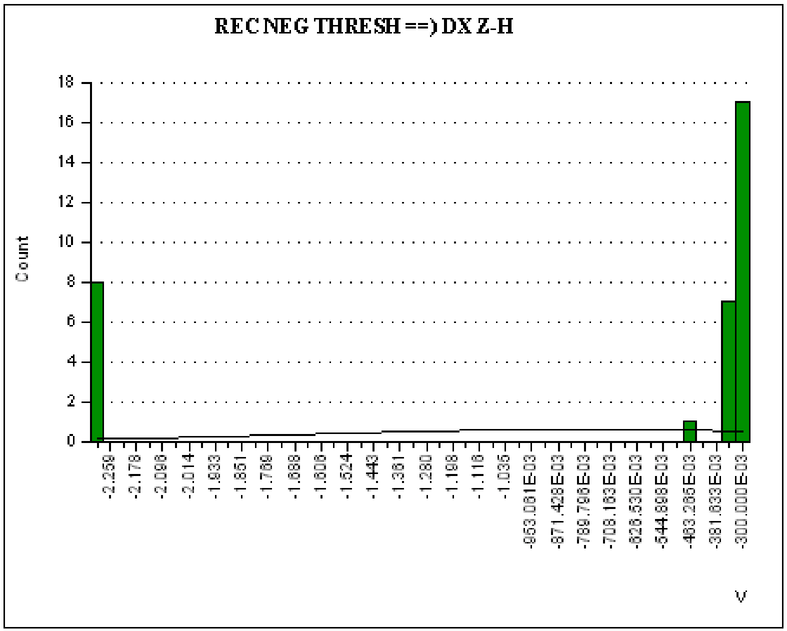
Min	-300.000E-03	**Skew**	3.9632
Max	-50.000E-03	**StatHigh**	N/A
Mean	-280.000E-03	**StatLow**	N/A
StdDev	48.423E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-134.730E-03	**90%**	-250.000E-03
		Range	250.000E-03
Mean-3*StdDev	-425.270E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.016, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-2.300	**StatLow**	N/A
Max	-300.000E-03	**NWithinSpec**	N/A
Mean	-800.000E-03	**NOutsideSpec**	N/A
StdDev	862.228E-03	**90%**	-300.000E-03
25%	-450.000E-03	**Range**	2.000
Mean+3*StdDev	1.787	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-3.387	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-1.2556		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

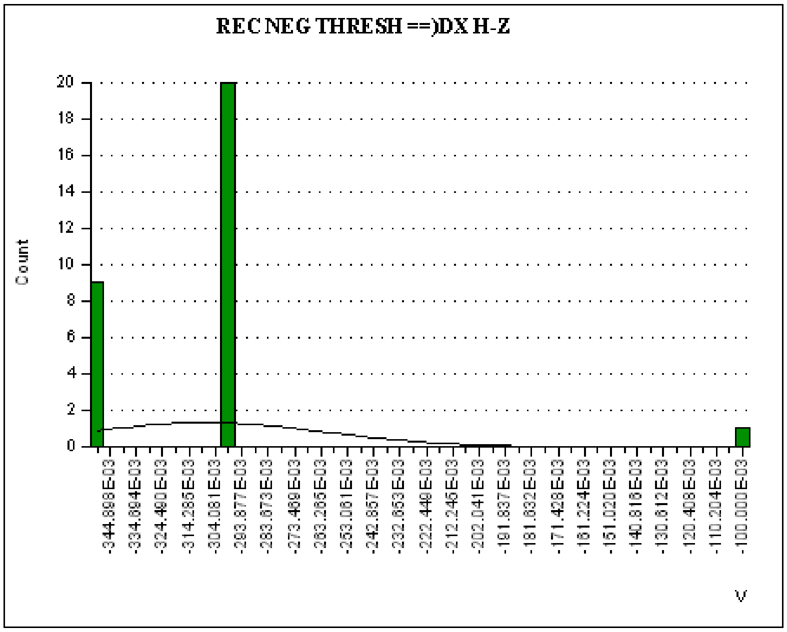
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.017, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

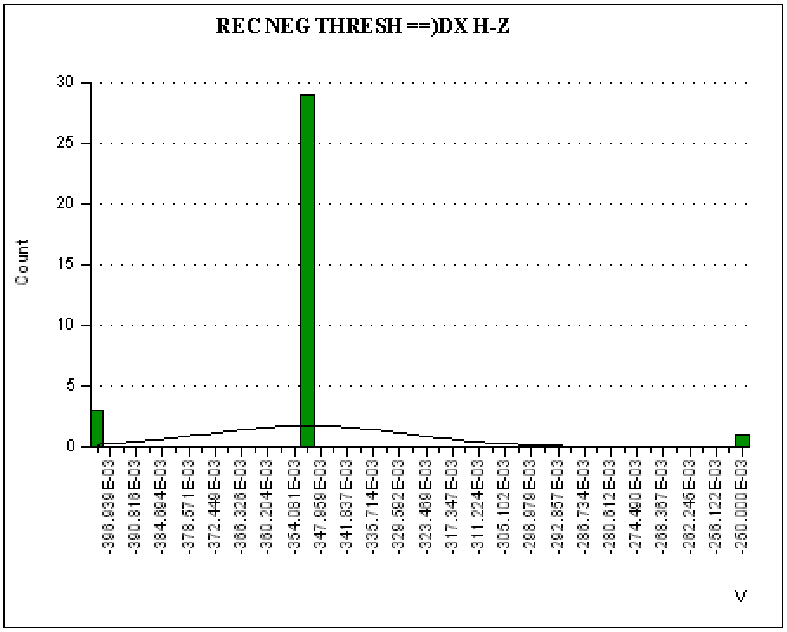
Min	-350.000E-03	**Skew**	3.2647
Max	-100.000E-03	**StatHigh**	N/A
Mean	-308.333E-03	**StatLow**	N/A
StdDev	45.644E-03	**NWithinSpec**	N/A
25%	-350.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-171.402E-03	**90%**	-300.000E-03
		Range	250.000E-03
Mean-3*StdDev	-445.264E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.017, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-400.000E-03	**StatLow**	N/A
Max	-250.000E-03	**NWithinSpec**	N/A
Mean	-351.515E-03	**NOutsideSpec**	N/A
StdDev	23.335E-03	**90%**	-350.000E-03
25%	-350.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-281.511E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-421.519E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.8440		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

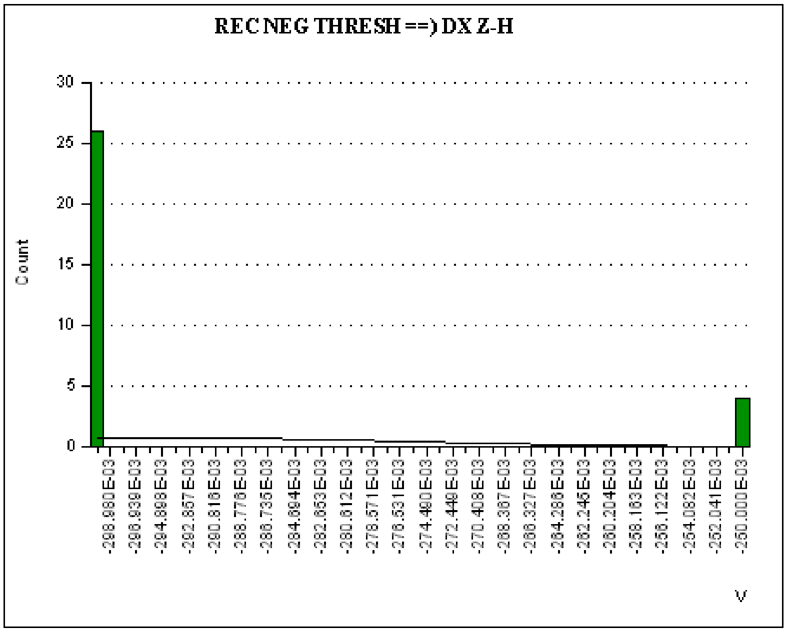
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.018, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

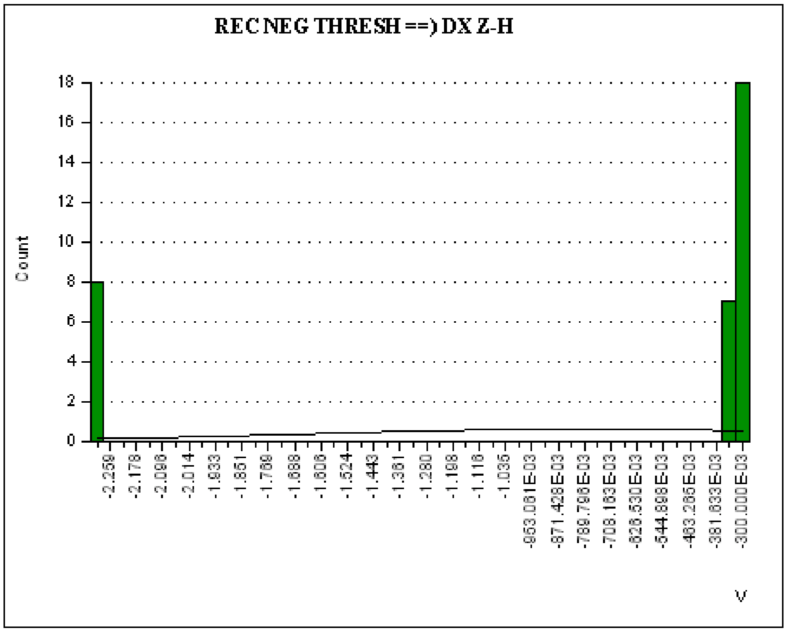
Min	-300.000E-03	**Skew**	2.2725
Max	-250.000E-03	**StatHigh**	N/A
Mean	-293.333E-03	**StatLow**	N/A
StdDev	17.287E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-241.471E-03	**90%**	-250.000E-03
		Range	50.000E-03
Mean-3*StdDev	-345.195E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.018, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-2.300	**StatLow**	N/A
Max	-300.000E-03	**NWithinSpec**	N/A
Mean	-795.454E-03	**NOutsideSpec**	N/A
StdDev	864.523E-03	**90%**	-300.000E-03
25%	-350.000E-03	**Range**	2.000
Mean+3*StdDev	1.798	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-3.389	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.2582		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

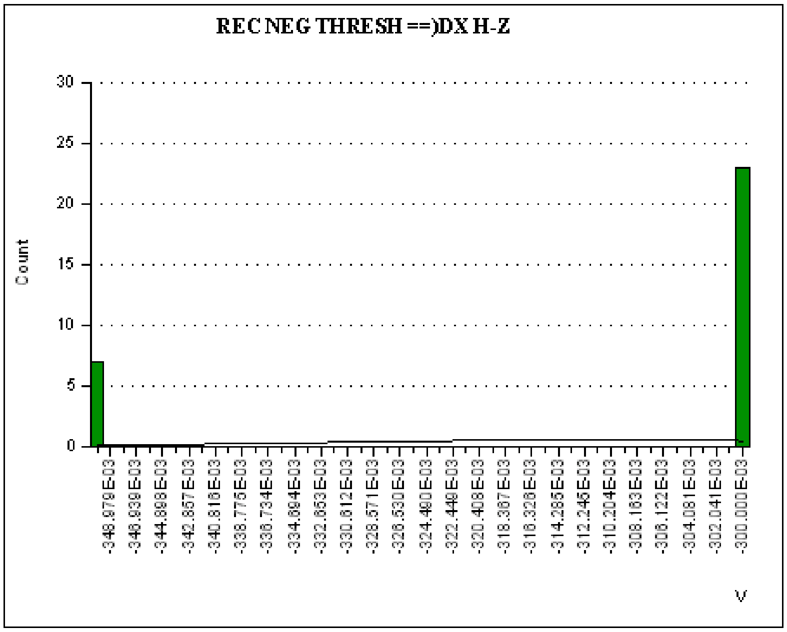
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=13.019, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

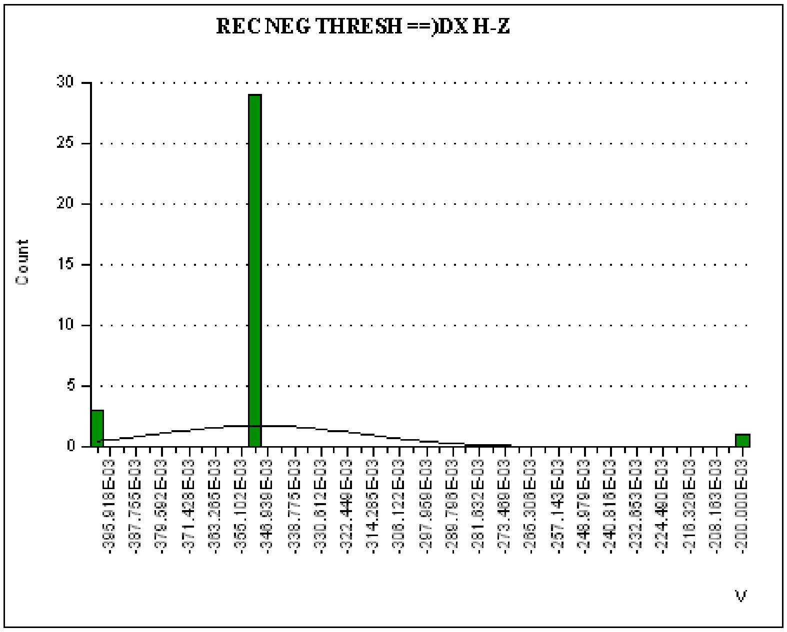
Min	-350.000E-03	**Skew**	-1.3283
Max	-300.000E-03	**StatHigh**	N/A
Mean	-311.666E-03	**StatLow**	N/A
StdDev	21.509E-03	**NWithinSpec**	N/A
25%	-300.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-247.139E-03	**90%**	-300.000E-03
		Range	50.000E-03
Mean-3*StdDev	-376.194E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.019, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-400.000E-03	**StatLow**	N/A
Max	-200.000E-03	**NWithinSpec**	N/A
Mean	-350.000E-03	**NOutsideSpec**	N/A
StdDev	30.619E-03	**90%**	-350.000E-03
25%	-350.000E-03	**Range**	200.000E-03
Mean+3*StdDev	-258.144E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-441.856E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	3.4767		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

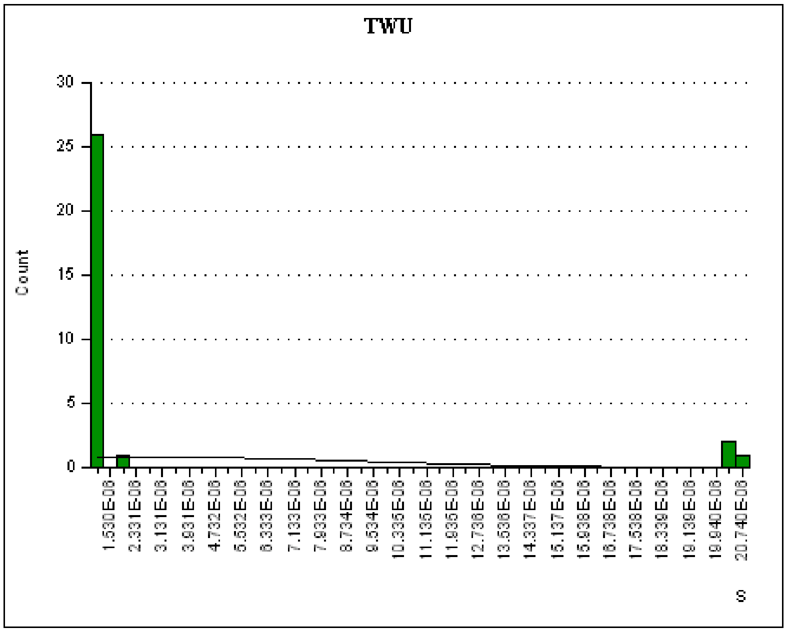
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=14.000, Test.Name=TWU



Statistics: (S)

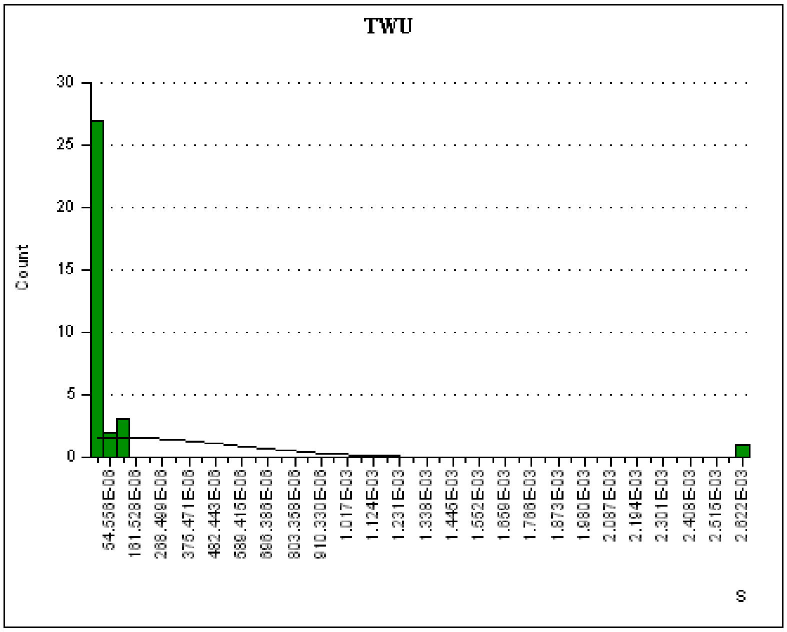
Min	1.130E-06	**Skew**	2.8059
Max	20.740E-06	**StatHigh**	N/A
Mean	3.155E-06	**StatLow**	N/A
StdDev	5.901E-06	**NWithinSpec**	N/A
25%	1.160E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	20.857E-06	**90%**	11.225E-06
		Range	19.610E-06
Mean-3*StdDev	-14.547E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=14.000, Test.Name=TWU



Statistics: (S)

Min	1.070E-06	**StatLow**	N/A
Max	2.622E-03	**NWithinSpec**	N/A
Mean	98.867E-06	**NOutsideSpec**	N/A
StdDev	454.132E-06	**90%**	99.450E-06
25%	1.990E-06	**Range**	2.621E-03
Mean+3*StdDev	1.461E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-1.264E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	5.6969		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

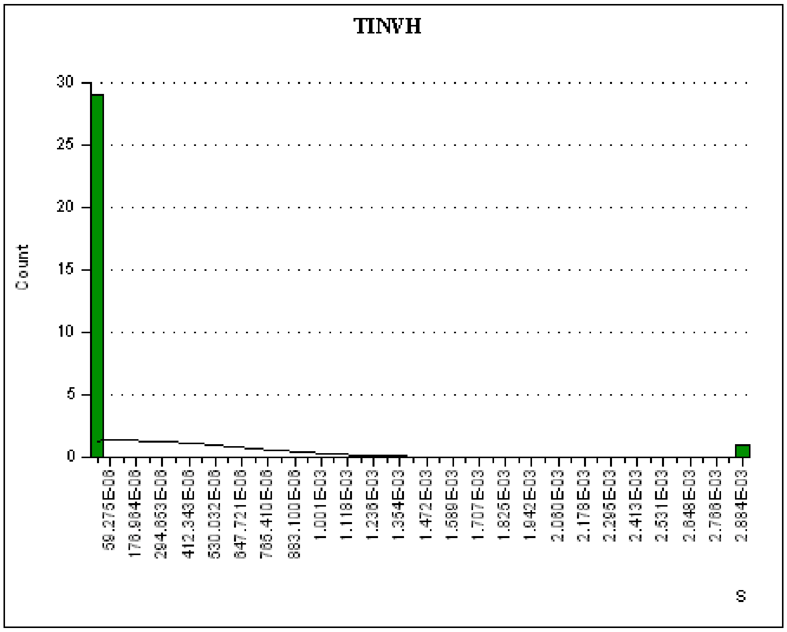
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=15.000, Test.Name=TINVH



Statistics: (S)

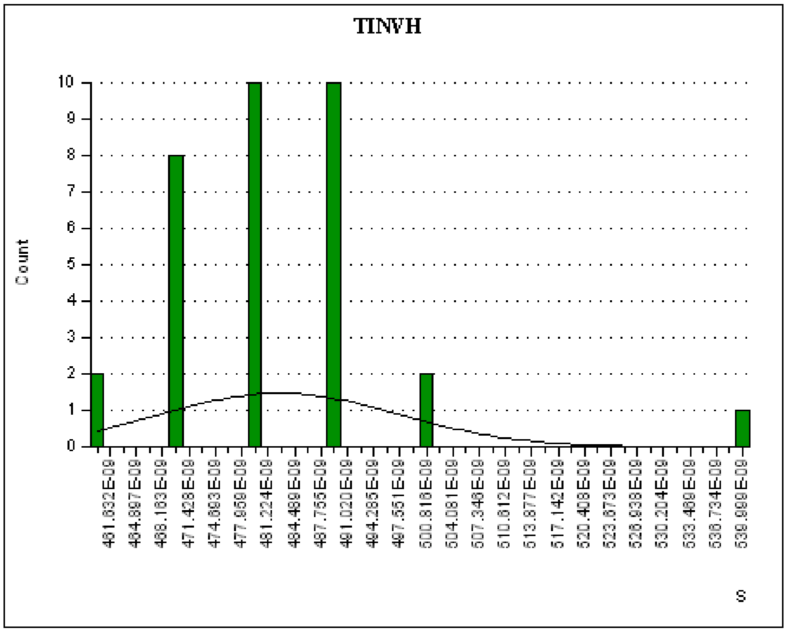
Min	430.000E-09	**Skew**	5.4772
Max	2.884E-03	**StatHigh**	N/A
Mean	96.608E-06	**StatLow**	N/A
StdDev	526.420E-06	**NWithinSpec**	N/A
25%	450.000E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	1.676E-03	**90%**	480.000E-09
		Range	2.883E-03
Mean-3*StdDev	-1.483E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=15.000, Test.Name=TINVH



Statistics: (S)

Min	460.000E-09	**StatLow**	N/A
Max	539.999E-09	**NWithinSpec**	N/A
Mean	482.424E-09	**NOutsideSpec**	N/A
StdDev	14.584E-09	**90%**	489.999E-09
25%	470.000E-09	**Range**	80.000E-09
Mean+3*StdDev	526.175E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	438.672E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.8021		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

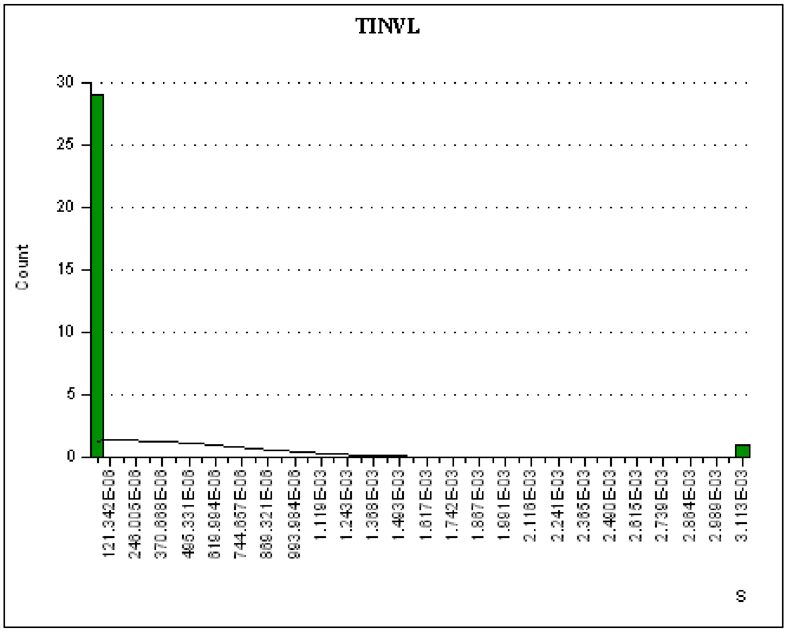
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=15.001, Test.Name=TINVL



Statistics: (S)

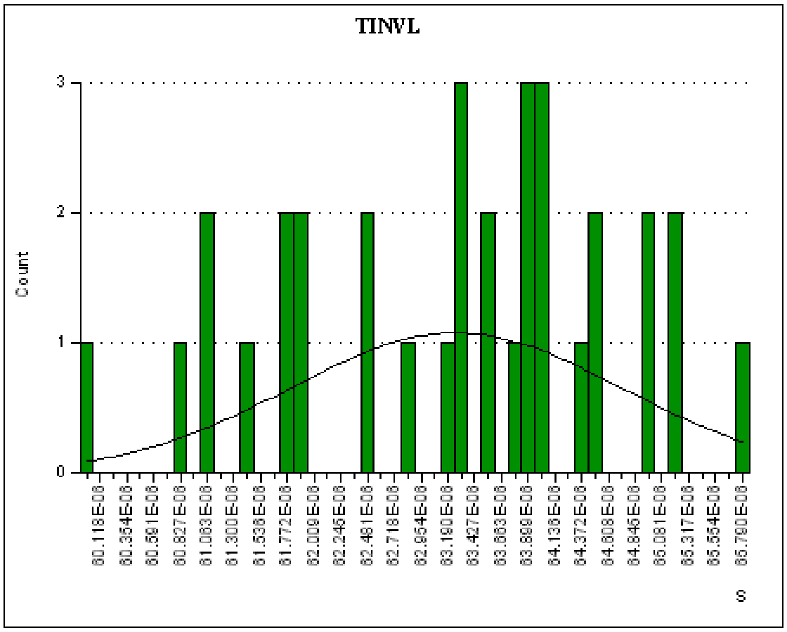
Min	59.010E-06	**Skew**	5.4772
Max	3.113E-03	**StatHigh**	N/A
Mean	162.570E-06	**StatLow**	N/A
StdDev	557.297E-06	**NWithinSpec**	N/A
25%	60.300E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.834E-03	**90%**	62.475E-06
		Range	3.054E-03
Mean-3*StdDev	-1.509E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=15.001, Test.Name=TINVL



Statistics: (S)

Min	60.000E-06	**StatLow**	N/A
Max	65.790E-06	**NWithinSpec**	N/A
Mean	63.231E-06	**NOutsideSpec**	N/A
StdDev	1.446E-06	**90%**	64.940E-06
25%	61.900E-06	**Range**	5.790E-06
Mean+3*StdDev	67.567E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	58.894E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.4051		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

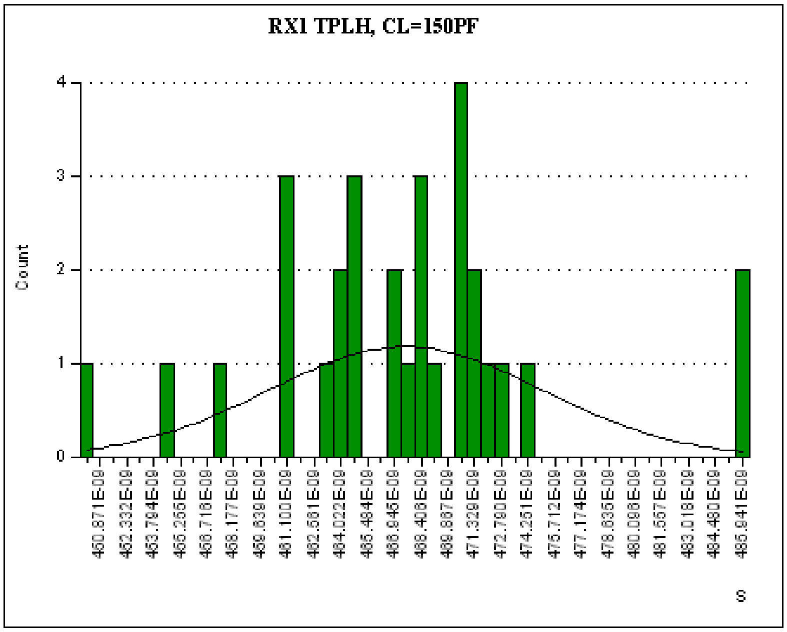
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.000, Test.Name=RX1 TPLH, CL=150PF



Statistics: (S)

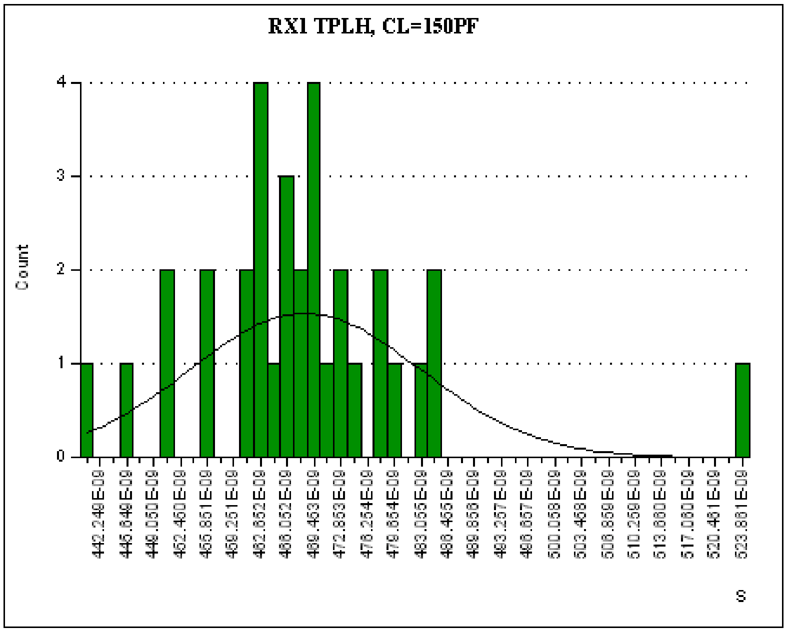
Min	450.141E-09	**Skew**	0.4036
Max	485.941E-09	**StatHigh**	N/A
Mean	467.398E-09	**StatLow**	N/A
StdDev	7.420E-09	**NWithinSpec**	N/A
25%	463.910E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	489.658E-09	**90%**	473.549E-09
		Range	35.800E-09
Mean-3*StdDev	445.138E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.000, Test.Name=RX1 TPLH, CL=150PF



Statistics: (S)

Min	440.548E-09	**StatLow**	N/A
Max	523.861E-09	**NWithinSpec**	N/A
Mean	468.007E-09	**NOutsideSpec**	N/A
StdDev	14.582E-09	**90%**	482.673E-09
25%	462.079E-09	**Range**	83.313E-09
Mean+3*StdDev	511.754E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	424.260E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.5102		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

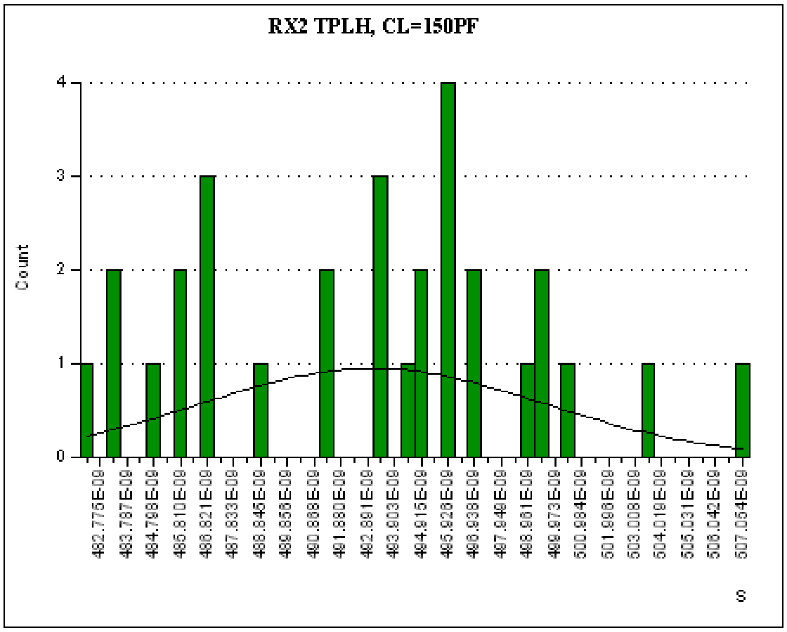
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.001, Test.Name=RX2 TPLH, CL=150PF



Statistics: (S)

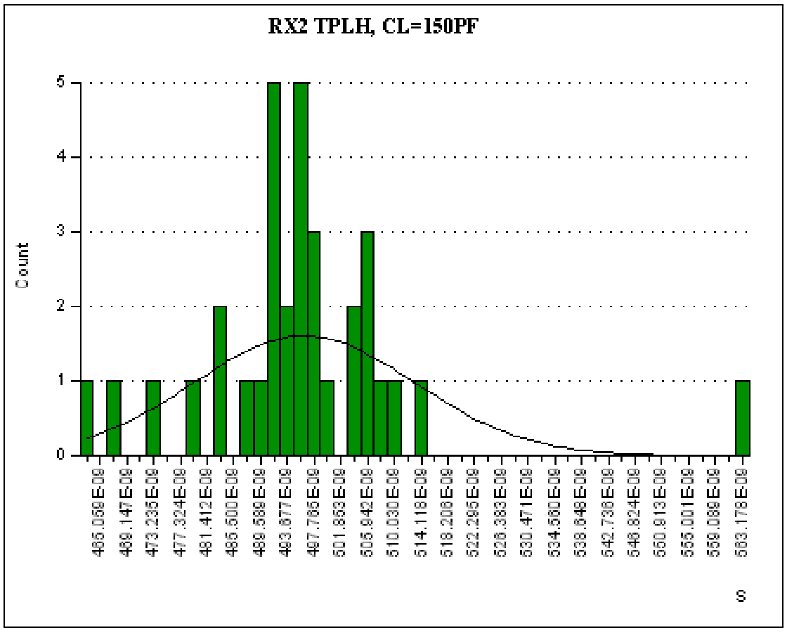
Min	482.269E-09	**Skew**	0.0504
Max	507.054E-09	**StatHigh**	N/A
Mean	492.979E-09	**StatLow**	N/A
StdDev	6.361E-09	**NWithinSpec**	N/A
25%	486.859E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	512.063E-09	**90%**	500.169E-09
		Range	24.785E-09
Mean-3*StdDev	473.895E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.001, Test.Name=RX2 TPLH, CL=150PF



Statistics: (S)

Min	463.015E-09	**StatLow**	N/A
Max	563.178E-09	**NWithinSpec**	N/A
Mean	495.948E-09	**NOutsideSpec**	N/A
StdDev	16.771E-09	**90%**	508.884E-09
25%	491.098E-09	**Range**	100.163E-09
Mean+3*StdDev	546.261E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	445.636E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.6660		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

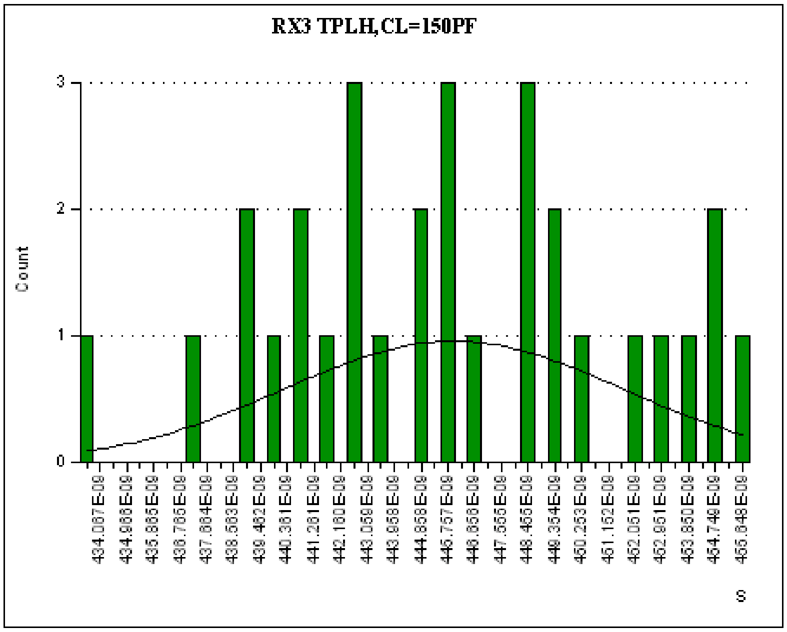
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.002, Test.Name=RX3 TPLH,CL=150PF



Statistics: (S)

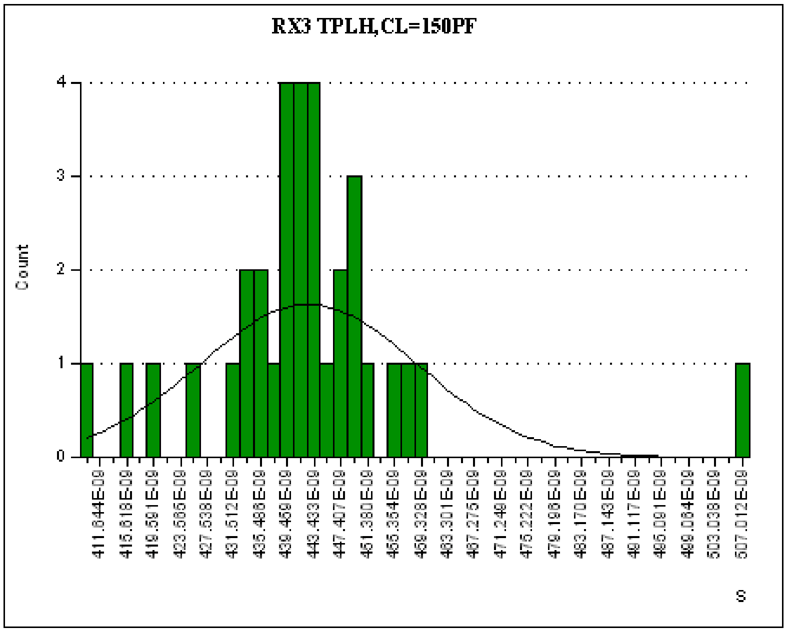
Min	433.617E-09	**Skew**	0.0071
Max	455.648E-09	**StatHigh**	N/A
Mean	445.826E-09	**StatLow**	N/A
StdDev	5.603E-09	**NWithinSpec**	N/A
25%	441.879E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	462.634E-09	**90%**	454.271E-09
		Range	22.031E-09
Mean-3*StdDev	429.018E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.002, Test.Name=RX3 TPLH,CL=150PF



Statistics: (S)

Min	409.657E-09	**StatLow**	N/A
Max	507.012E-09	**NWithinSpec**	N/A
Mean	442.222E-09	**NOutsideSpec**	N/A
StdDev	15.999E-09	**90%**	454.590E-09
25%	435.868E-09	**Range**	97.354E-09
Mean+3*StdDev	490.219E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	394.225E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.7196		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

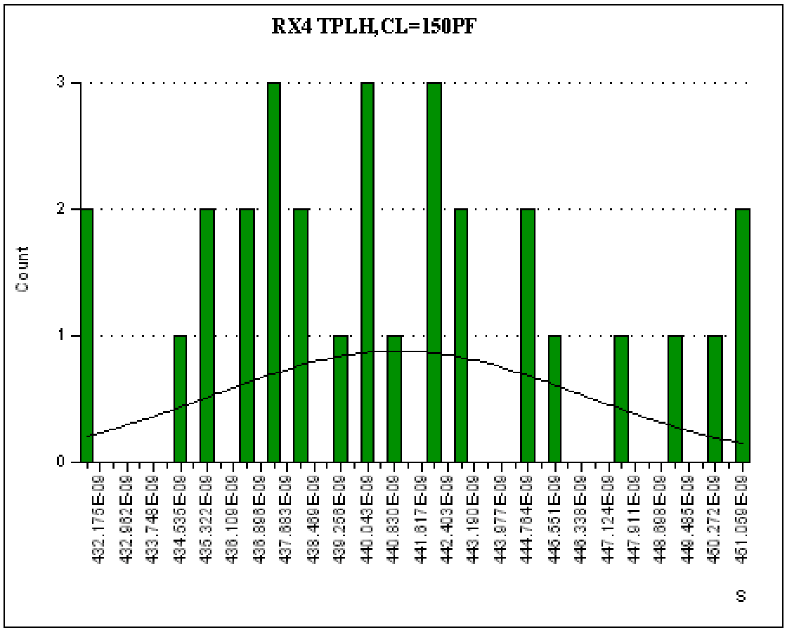
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.003, Test.Name=RX4 TPLH,CL=150PF



Statistics: (S)

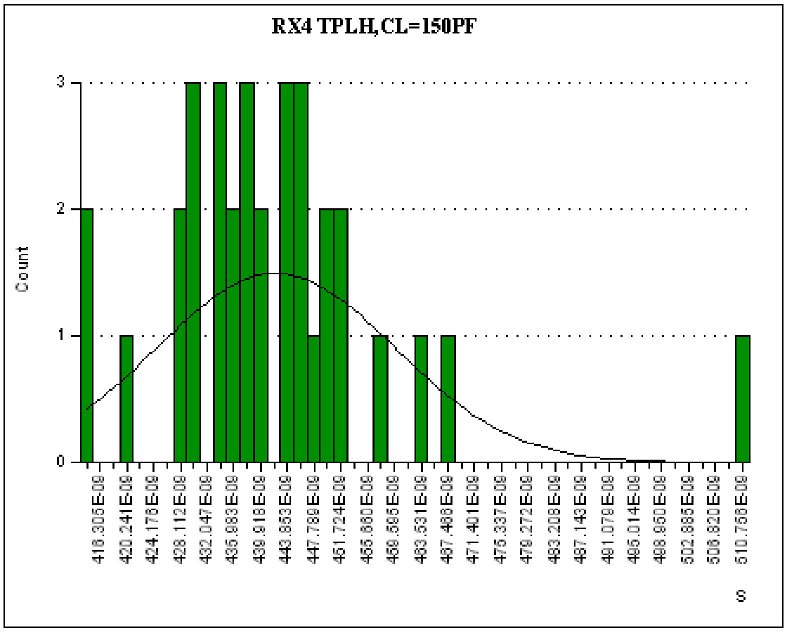
Min	431.781E-09	**Skew**	0.3961
Max	451.059E-09	**StatHigh**	N/A
Mean	440.839E-09	**StatLow**	N/A
StdDev	5.346E-09	**NWithinSpec**	N/A
25%	437.289E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	456.876E-09	**90%**	449.682E-09
		Range	19.277E-09
Mean-3*StdDev	424.801E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.003, Test.Name=RX4 TPLH,CL=150PF



Statistics: (S)

Min	414.338E-09	**StatLow**	N/A
Max	510.756E-09	**NWithinSpec**	N/A
Mean	441.825E-09	**NOutsideSpec**	N/A
StdDev	17.357E-09	**90%**	457.398E-09
25%	433.060E-09	**Range**	96.418E-09
Mean+3*StdDev	493.896E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	389.754E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.8901		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

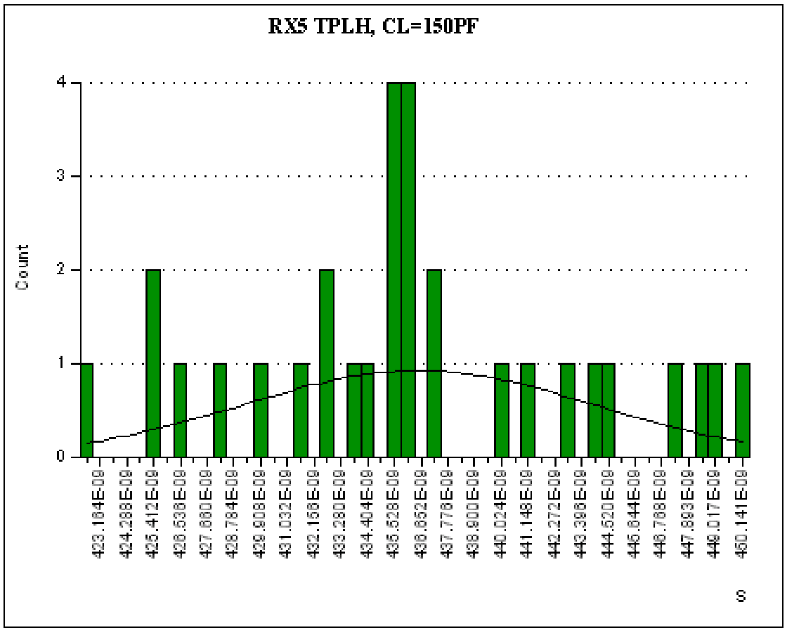
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.004, Test.Name=RX5 TPLH, CL=150PF



Statistics: (S)

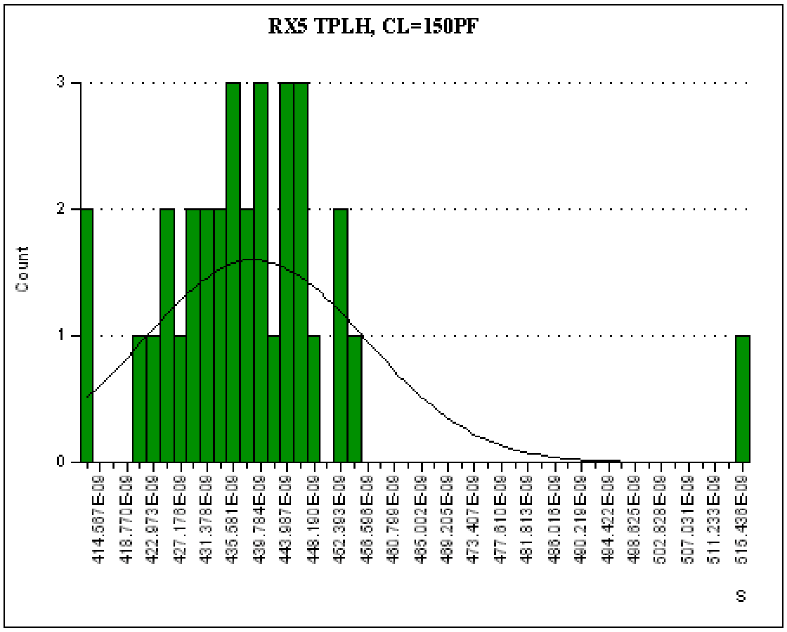
Min	422.602E-09	**Skew**	0.1584
Max	450.141E-09	**StatHigh**	N/A
Mean	436.402E-09	**StatLow**	N/A
StdDev	7.250E-09	**NWithinSpec**	N/A
25%	432.699E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	458.152E-09	**90%**	447.846E-09
		Range	27.539E-09
Mean-3*StdDev	414.652E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.004, Test.Name=RX5 TPLH, CL=150PF



Statistics: (S)

Min	412.465E-09	**StatLow**	N/A
Max	515.436E-09	**NWithinSpec**	N/A
Mean	438.478E-09	**NOutsideSpec**	N/A
StdDev	17.275E-09	**90%**	451.782E-09
25%	430.251E-09	**Range**	102.971E-09
Mean+3*StdDev	490.302E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	386.653E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	2.6818		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

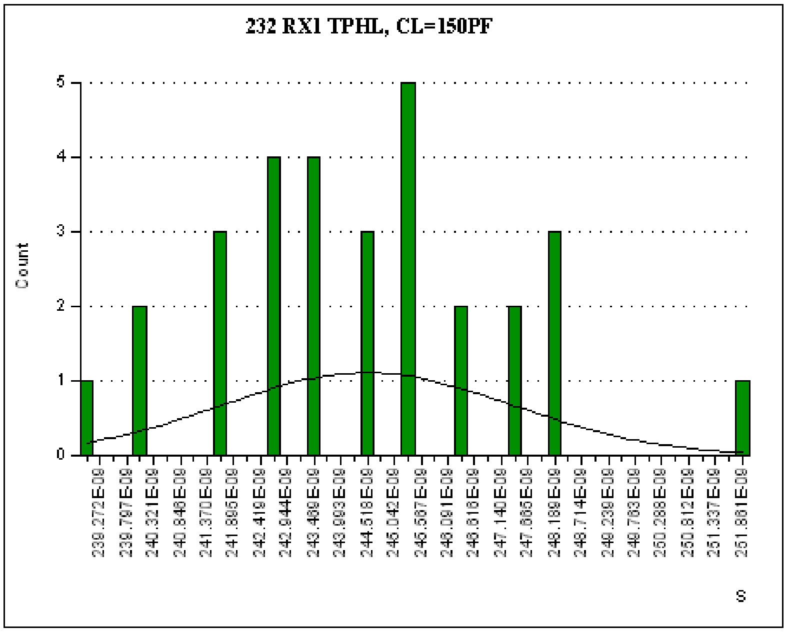
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.005, Test.Name=232 RX1 TPHL, CL=150PF



Statistics: (S)

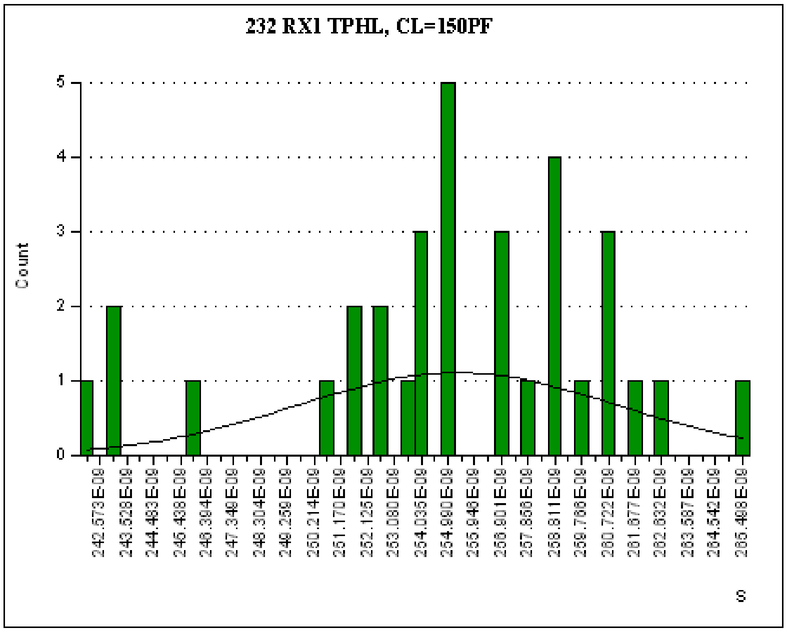
Min	239.010E-09	**Skew**	0.3163
Max	251.861E-09	**StatHigh**	N/A
Mean	244.456E-09	**StatLow**	N/A
StdDev	2.831E-09	**NWithinSpec**	N/A
25%	242.682E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	252.950E-09	**90%**	248.189E-09
		Range	12.851E-09
Mean-3*StdDev	235.963E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.005, Test.Name=232 RX1 TPHL, CL=150PF



Statistics: (S)

Min	242.095E-09	**StatLow**	N/A
Max	265.498E-09	**NWithinSpec**	N/A
Mean	255.201E-09	**NOutsideSpec**	N/A
StdDev	5.655E-09	**90%**	260.817E-09
25%	252.392E-09	**Range**	23.403E-09
Mean+3*StdDev	272.167E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	238.234E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.7829		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

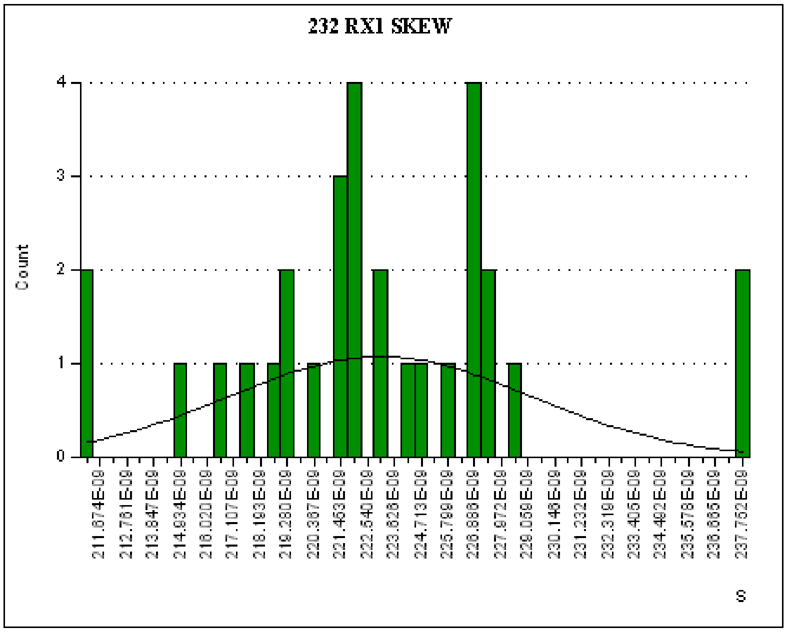
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.006, Test.Name=232 RX1 SKEW



Statistics: (S)

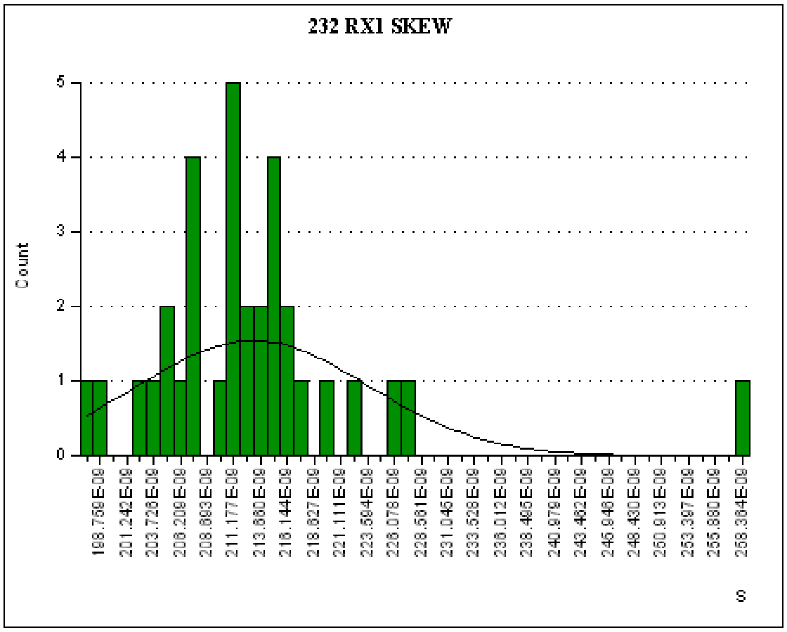
Min	211.131E-09	**Skew**	0.4462
Max	237.752E-09	**StatHigh**	N/A
Mean	222.942E-09	**StatLow**	N/A
StdDev	6.054E-09	**NWithinSpec**	N/A
25%	219.392E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	241.105E-09	**90%**	228.113E-09
		Range	26.621E-09
Mean-3*StdDev	204.779E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.006, Test.Name=232 RX1 SKEW



Statistics: (S)

Min	197.517E-09	**StatLow**	N/A
Max	258.364E-09	**NWithinSpec**	N/A
Mean	212.807E-09	**NOutsideSpec**	N/A
StdDev	10.626E-09	**90%**	221.856E-09
25%	206.878E-09	**Range**	60.847E-09
Mean+3*StdDev	244.685E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	180.929E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	2.5056		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

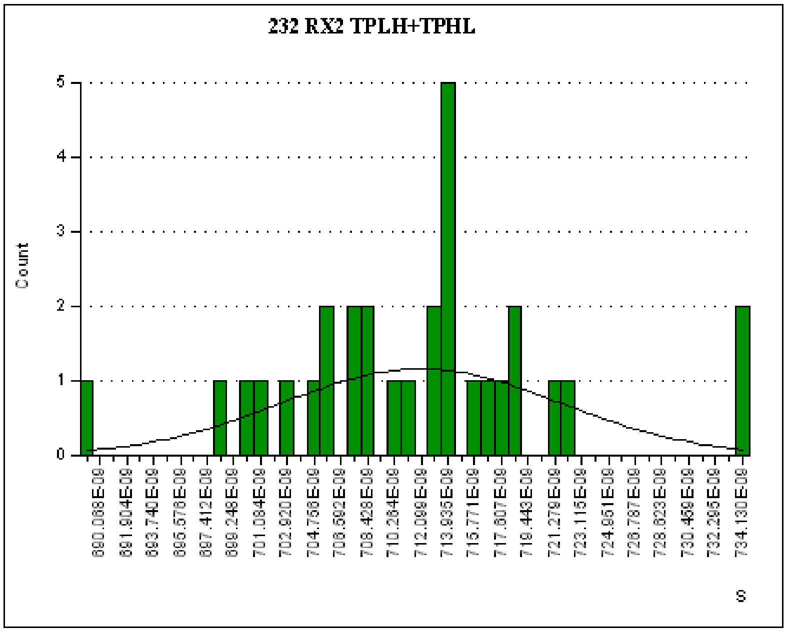
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.007, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

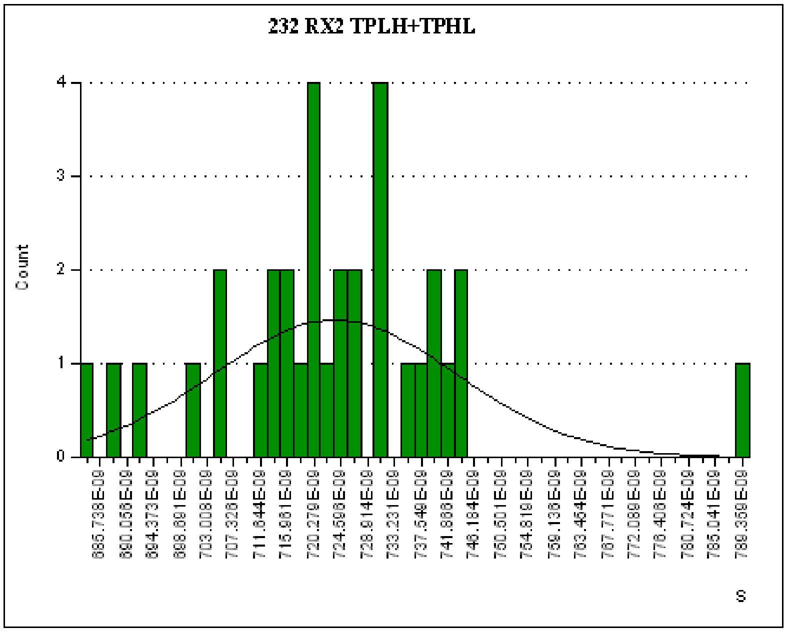
Min	689.150E-09	**Skew**	0.2723
Max	734.130E-09	**StatHigh**	N/A
Mean	711.855E-09	**StatLow**	N/A
StdDev	9.460E-09	**NWithinSpec**	N/A
25%	705.674E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	740.235E-09	**90%**	721.738E-09
		Range	44.980E-09
Mean-3*StdDev	683.475E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.007, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

Min	683.580E-09	**StatLow**	N/A
Max	789.359E-09	**NWithinSpec**	N/A
Mean	723.208E-09	**NOutsideSpec**	N/A
StdDev	19.400E-09	**90%**	741.618E-09
25%	714.471E-09	**Range**	105.779E-09
Mean+3*StdDev	781.407E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	665.009E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.7584		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

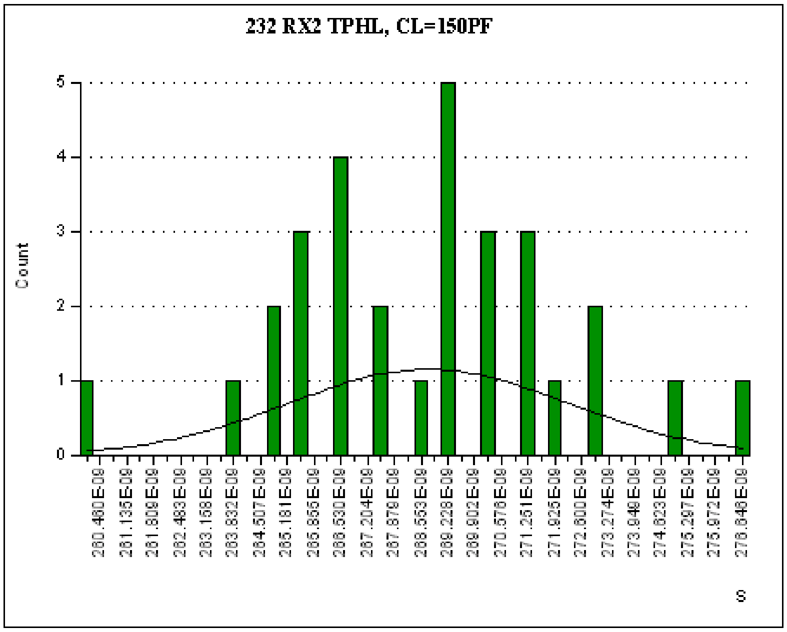
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.008, Test.Name=232 RX2 TPHL, CL=150PF



Statistics: (S)

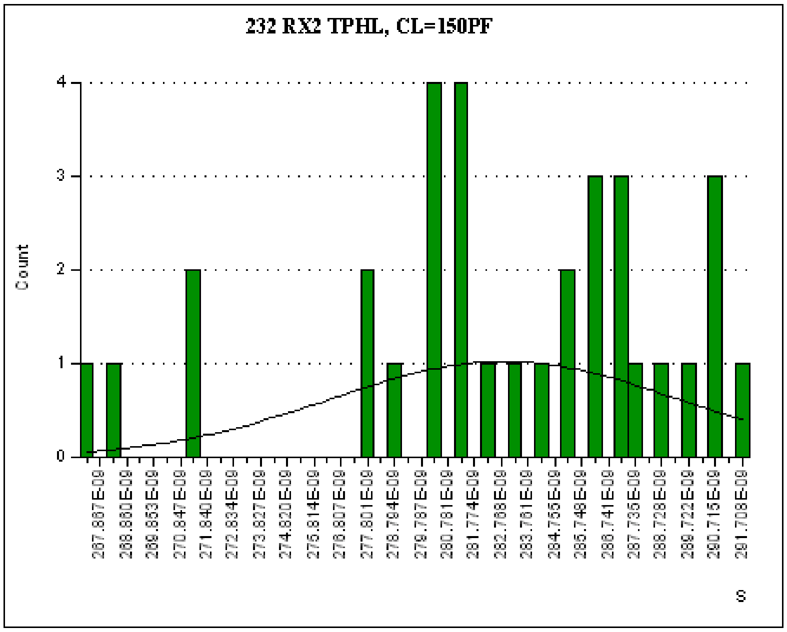
Min	260.123E-09	**Skew**	0.0133
Max	276.646E-09	**StatHigh**	N/A
Mean	268.660E-09	**StatLow**	N/A
StdDev	3.495E-09	**NWithinSpec**	N/A
25%	266.549E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	279.144E-09	**90%**	272.974E-09
		Range	16.523E-09
Mean-3*StdDev	258.176E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.008, Test.Name=232 RX2 TPHL, CL=150PF



Statistics: (S)

Min	267.370E-09	**StatLow**	N/A
Max	291.708E-09	**NWithinSpec**	N/A
Mean	282.716E-09	**NOutsideSpec**	N/A
StdDev	6.383E-09	**90%**	290.772E-09
25%	280.475E-09	**Range**	24.339E-09
Mean+3*StdDev	301.865E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	263.567E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.8551		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

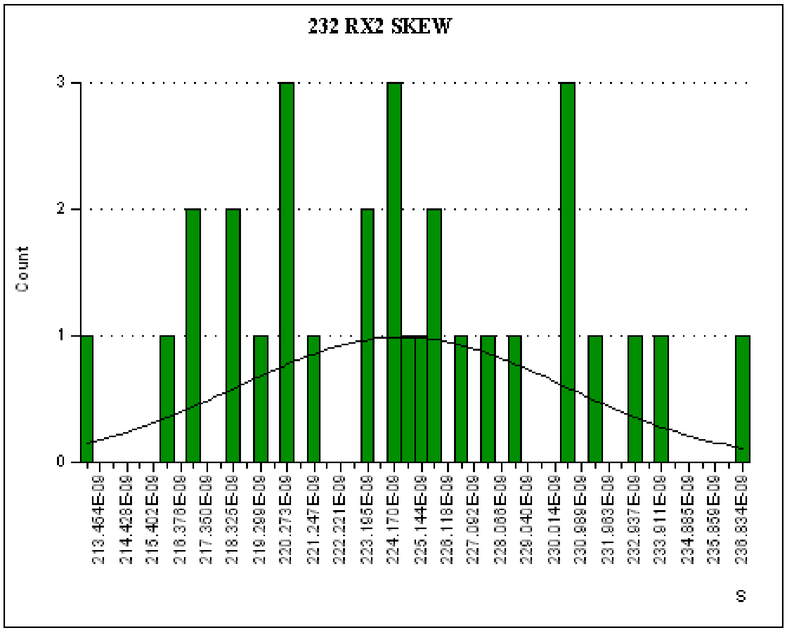
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.009, Test.Name=232 RX2 SKEW



Statistics: (S)

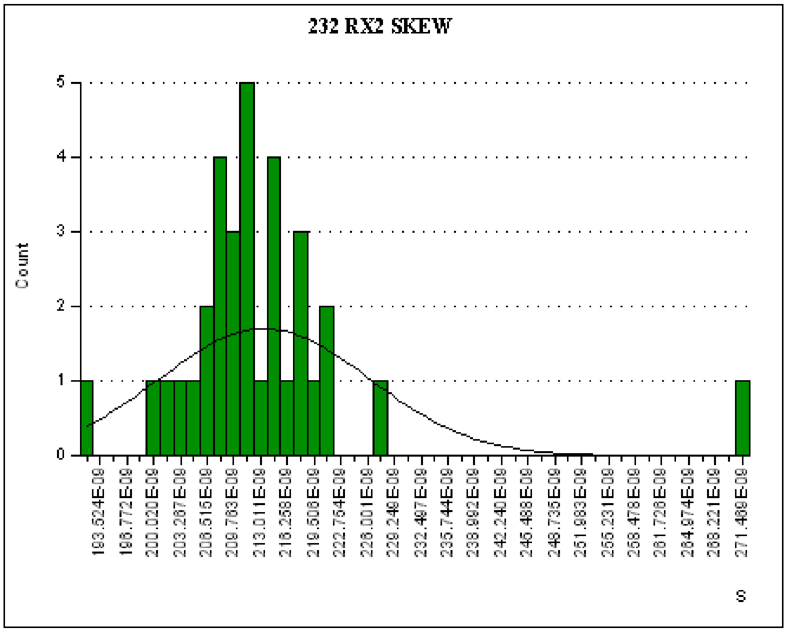
Min	212.967E-09	**Skew**	0.1789
Max	236.834E-09	**StatHigh**	N/A
Mean	224.319E-09	**StatLow**	N/A
StdDev	5.888E-09	**NWithinSpec**	N/A
25%	220.310E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	241.982E-09	**90%**	232.244E-09
		Range	23.867E-09
Mean-3*StdDev	206.656E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.009, Test.Name=232 RX2 SKEW



Statistics: (S)

Min	191.901E-09	**StatLow**	N/A
Max	271.469E-09	**NWithinSpec**	N/A
Mean	213.232E-09	**NOutsideSpec**	N/A
StdDev	12.559E-09	**90%**	221.856E-09
25%	208.750E-09	**Range**	79.569E-09
Mean+3*StdDev	250.908E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	175.557E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	3.1145		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

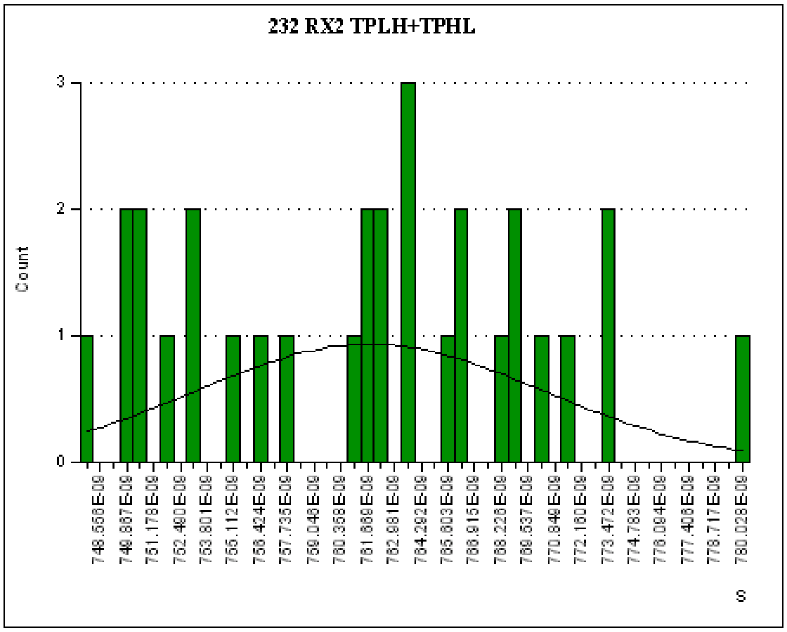
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.010, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

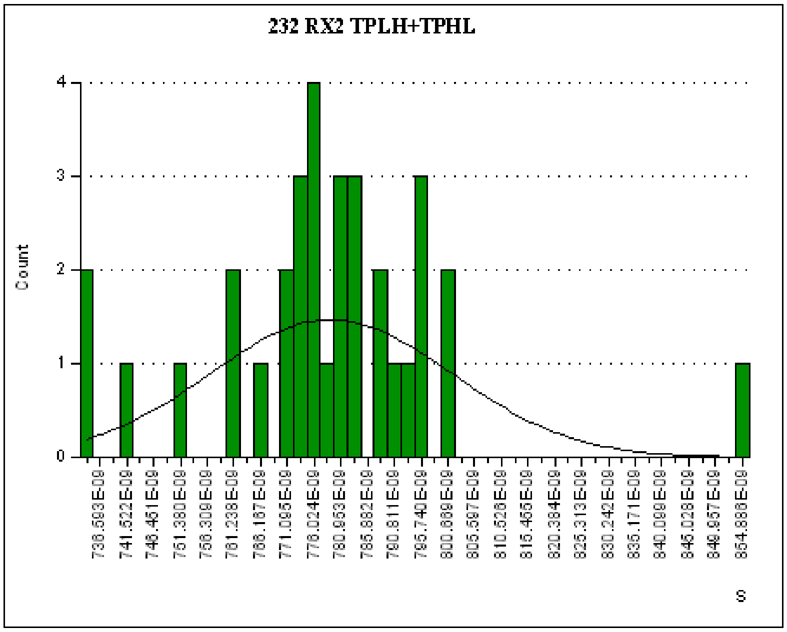
Min	747.900E-09	**Skew**	0.0849
Max	780.028E-09	**StatHigh**	N/A
Mean	761.639E-09	**StatLow**	N/A
StdDev	8.408E-09	**NWithinSpec**	N/A
25%	753.408E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	786.863E-09	**90%**	772.685E-09
		Range	32.129E-09
Mean-3*StdDev	736.415E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.010, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

Min	734.129E-09	**StatLow**	N/A
Max	854.886E-09	**NWithinSpec**	N/A
Mean	778.665E-09	**NOutsideSpec**	N/A
StdDev	22.052E-09	**90%**	796.848E-09
25%	771.573E-09	**Range**	120.757E-09
Mean+3*StdDev	844.820E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	712.509E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.6862		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

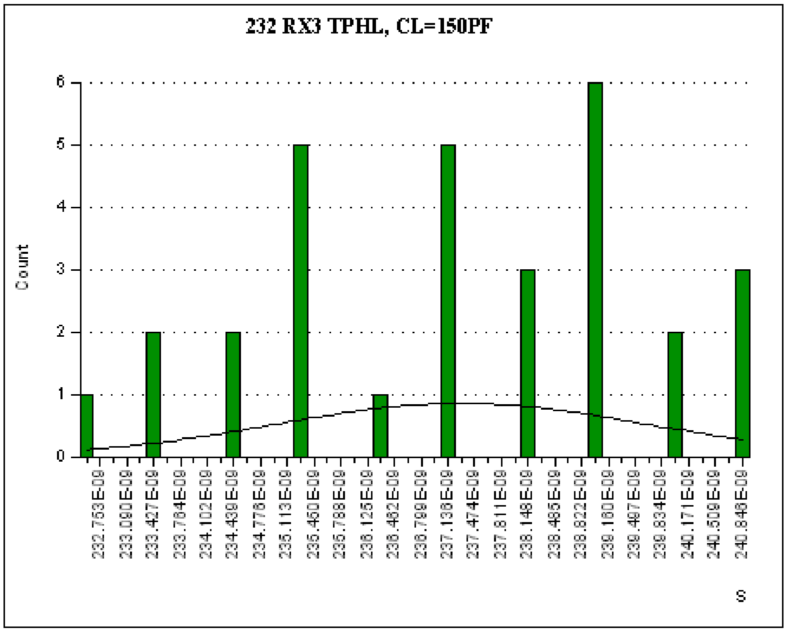
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.011, Test.Name=232 RX3 TPHL, CL=150PF



Statistics: (S)

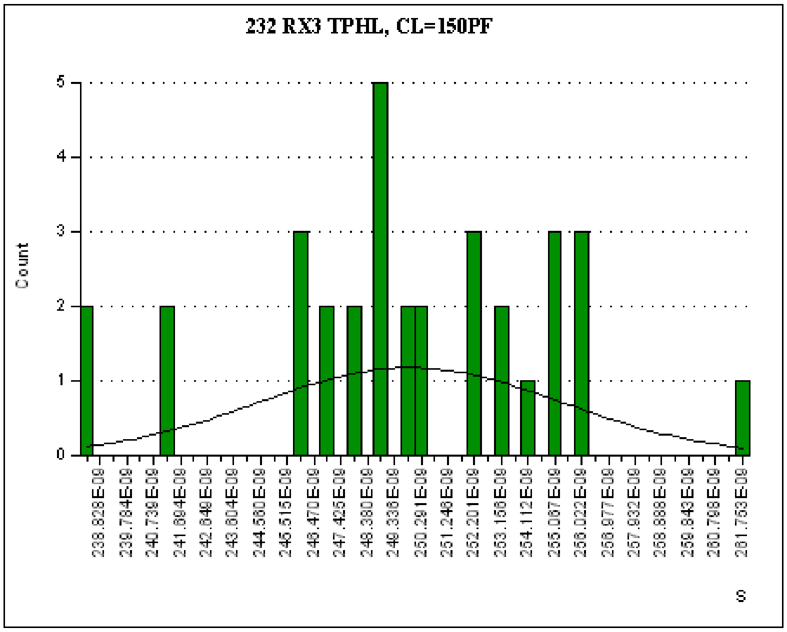
Min	232.584E-09	**Skew**	-0.2396
Max	240.846E-09	**StatHigh**	N/A
Mean	237.266E-09	**StatLow**	N/A
StdDev	2.342E-09	**NWithinSpec**	N/A
25%	235.338E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	244.291E-09	**90%**	240.387E-09
		Range	8.262E-09
Mean-3*StdDev	230.241E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.011, Test.Name=232 RX3 TPHL, CL=150PF



Statistics: (S)

Min	238.351E-09	**StatLow**	N/A
Max	261.753E-09	**NWithinSpec**	N/A
Mean	249.782E-09	**NOutsideSpec**	N/A
StdDev	5.330E-09	**90%**	256.137E-09
25%	246.776E-09	**Range**	23.403E-09
Mean+3*StdDev	265.773E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	233.792E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.2940		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

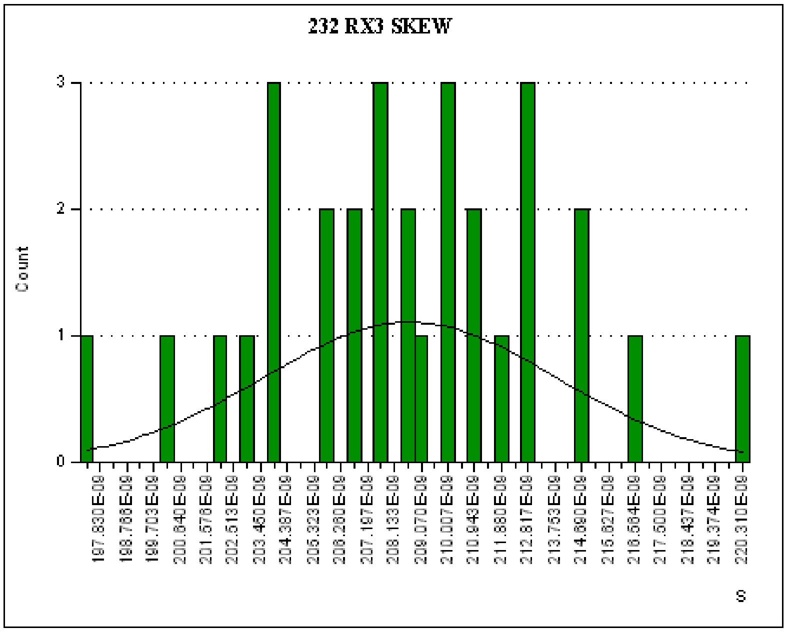
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.012, Test.Name=232 RX3 SKEW



Statistics: (S)

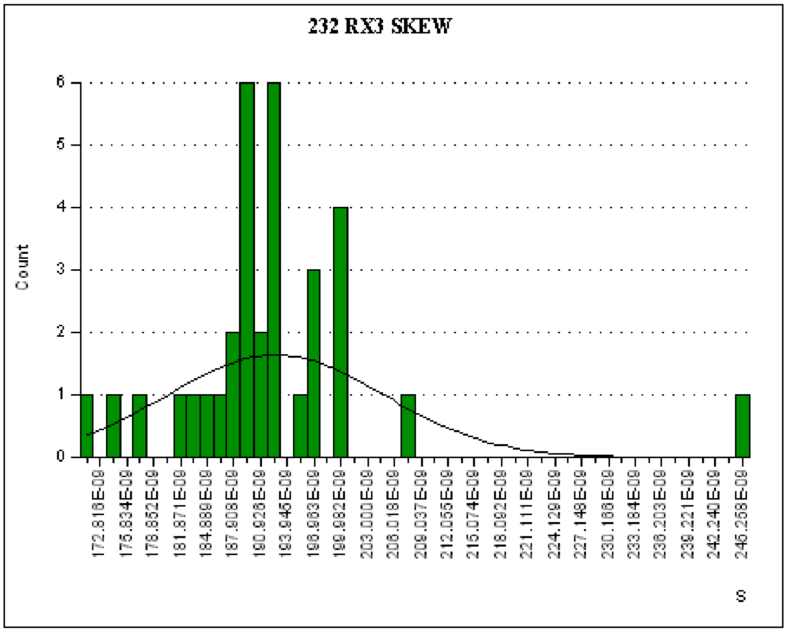
Min	197.361E-09	**Skew**	0.0299
Max	220.310E-09	**StatHigh**	N/A
Mean	208.560E-09	**StatLow**	N/A
StdDev	5.065E-09	**NWithinSpec**	N/A
25%	205.623E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	223.755E-09	**90%**	214.803E-09
		Range	22.949E-09
Mean-3*StdDev	193.366E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.012, Test.Name=232 RX3 SKEW



Statistics: (S)

Min	171.306E-09	**StatLow**	N/A
Max	245.258E-09	**NWithinSpec**	N/A
Mean	192.440E-09	**NOutsideSpec**	N/A
StdDev	12.124E-09	**90%**	200.325E-09
25%	188.156E-09	**Range**	73.952E-09
Mean+3*StdDev	228.812E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	156.067E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.4434		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

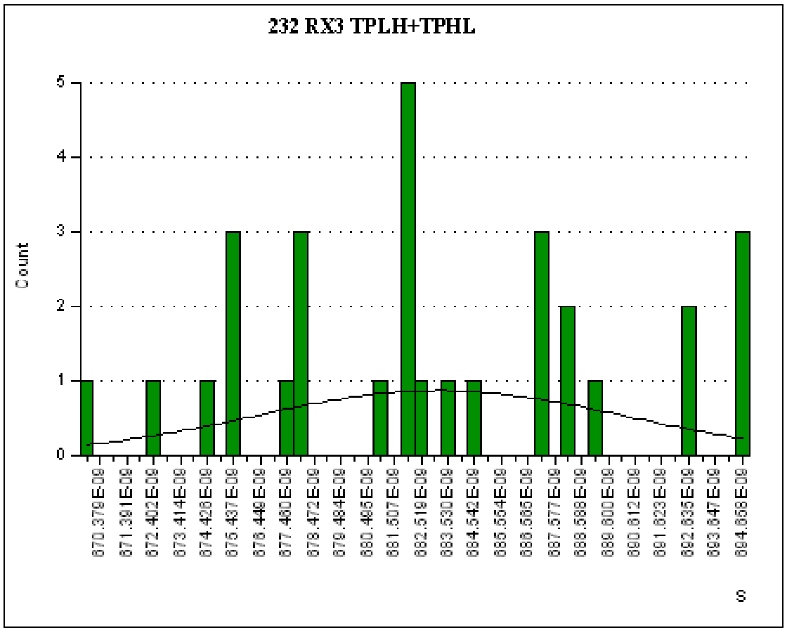
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.013, Test.Name=232 RX3 TPLH+TPHL



Statistics: (S)

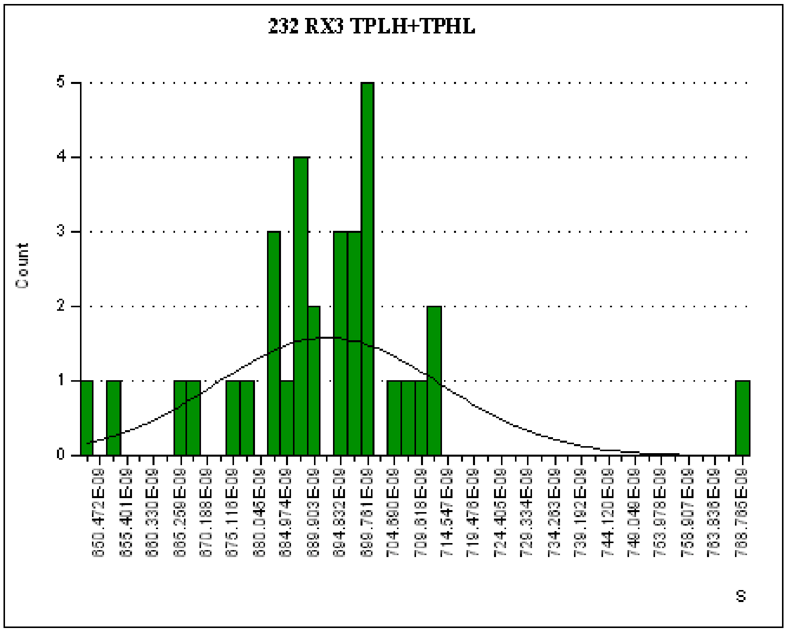
Min	669.873E-09	**Skew**	0.1268
Max	694.658E-09	**StatHigh**	N/A
Mean	683.092E-09	**StatLow**	N/A
StdDev	6.935E-09	**NWithinSpec**	N/A
25%	678.135E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	703.897E-09	**90%**	693.740E-09
		Range	24.785E-09
Mean-3*StdDev	662.287E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.013, Test.Name=232 RX3 TPLH+TPHL



Statistics: (S)

Min	648.008E-09	**StatLow**	N/A
Max	768.765E-09	**NWithinSpec**	N/A
Mean	692.005E-09	**NOutsideSpec**	N/A
StdDev	20.537E-09	**90%**	709.790E-09
25%	682.644E-09	**Range**	120.757E-09
Mean+3*StdDev	753.615E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	630.394E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.1335		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

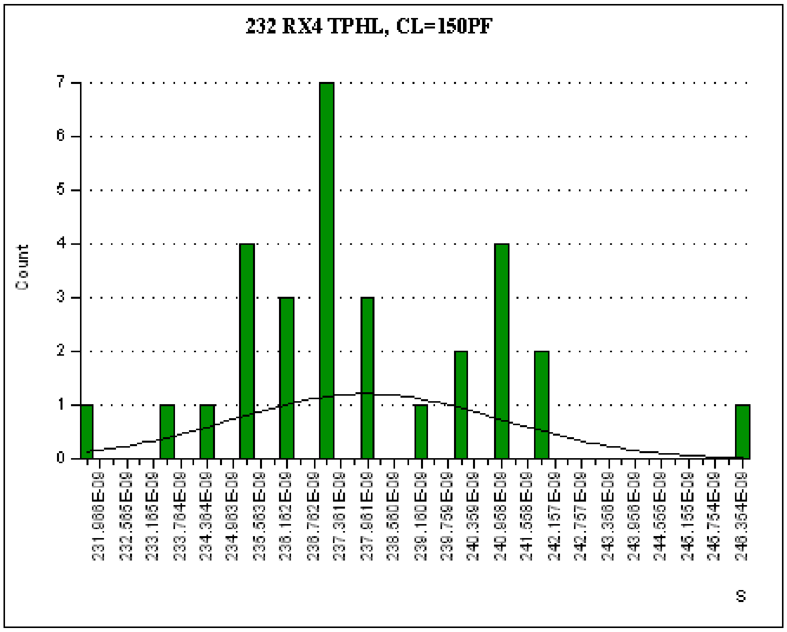
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.014, Test.Name=232 RX4 TPHL, CL=150PF



Statistics: (S)

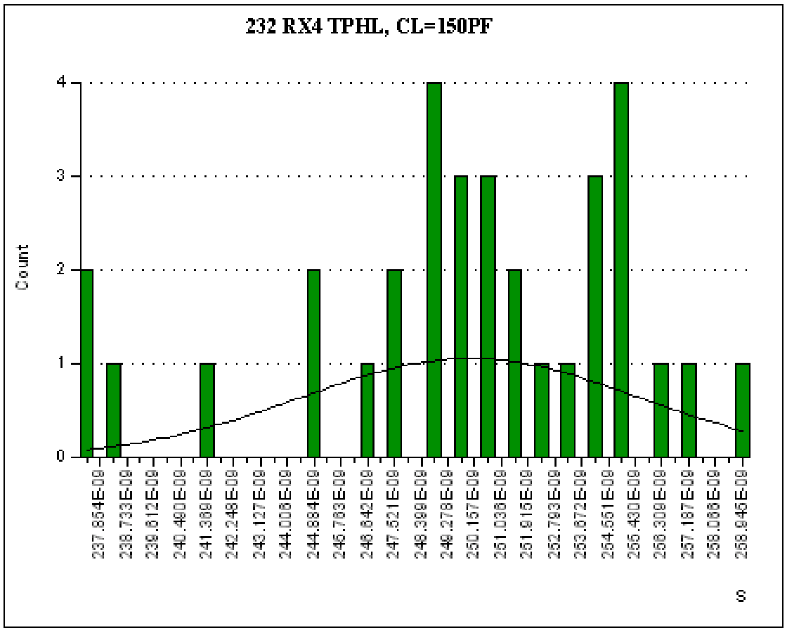
Min	231.666E-09	**Skew**	0.5761
Max	246.354E-09	**StatHigh**	N/A
Mean	237.878E-09	**StatLow**	N/A
StdDev	2.959E-09	**NWithinSpec**	N/A
25%	236.256E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	246.755E-09	**90%**	241.305E-09
		Range	14.687E-09
Mean-3*StdDev	229.000E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.014, Test.Name=232 RX4 TPHL, CL=150PF



Statistics: (S)

Min	237.415E-09	**StatLow**	N/A
Max	258.945E-09	**NWithinSpec**	N/A
Mean	249.868E-09	**NOutsideSpec**	N/A
StdDev	5.486E-09	**90%**	255.201E-09
25%	247.712E-09	**Range**	21.530E-09
Mean+3*StdDev	266.325E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	233.410E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.8172		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

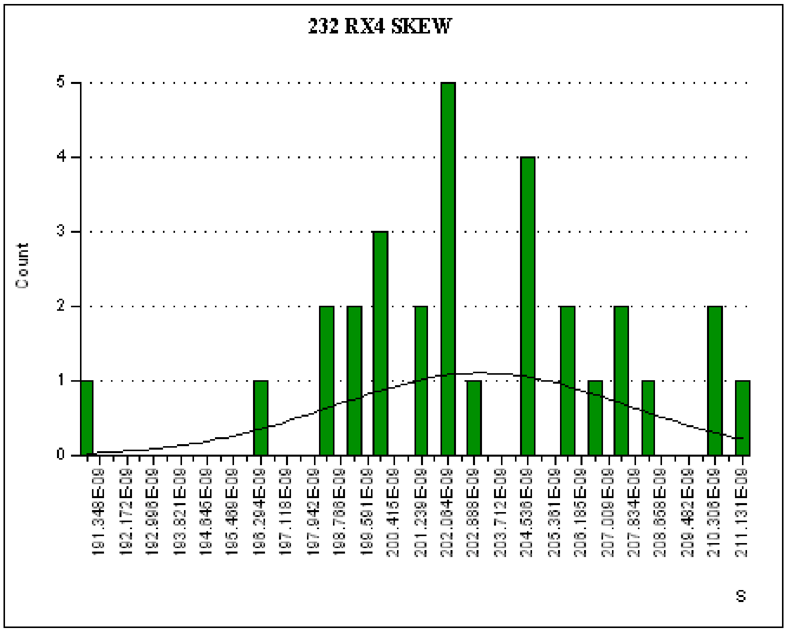
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.015, Test.Name=232 RX4 SKEW



Statistics: (S)

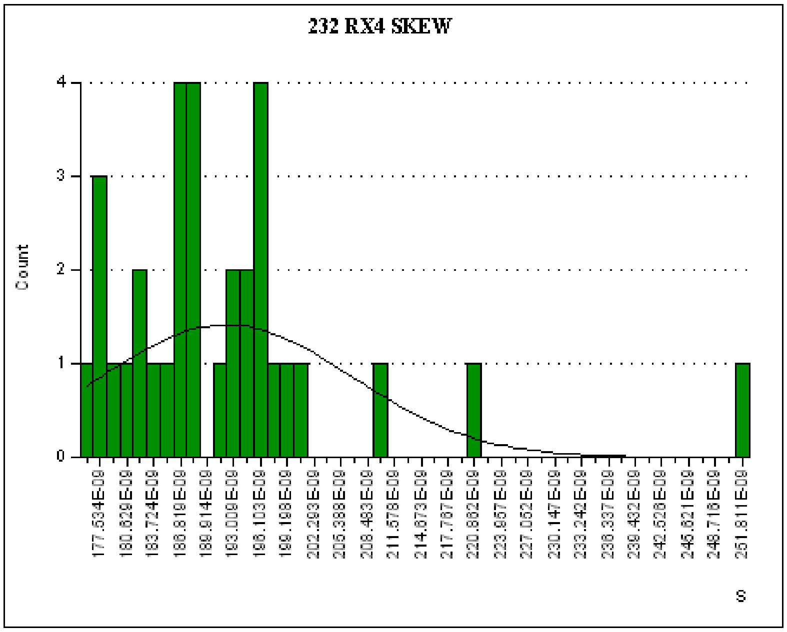
Min	190.936E-09	**Skew**	-0.2758
Max	211.131E-09	**StatHigh**	N/A
Mean	202.961E-09	**StatLow**	N/A
StdDev	4.460E-09	**NWithinSpec**	N/A
25%	200.115E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	216.342E-09	**90%**	209.295E-09
		Range	20.195E-09
Mean-3*StdDev	189.580E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.015, Test.Name=232 RX4 SKEW



Statistics: (S)

Min	175.987E-09	**StatLow**	N/A
Max	251.811E-09	**NWithinSpec**	N/A
Mean	191.957E-09	**NOutsideSpec**	N/A
StdDev	14.394E-09	**90%**	201.262E-09
25%	184.412E-09	**Range**	75.824E-09
Mean+3*StdDev	235.139E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	148.776E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.5285		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

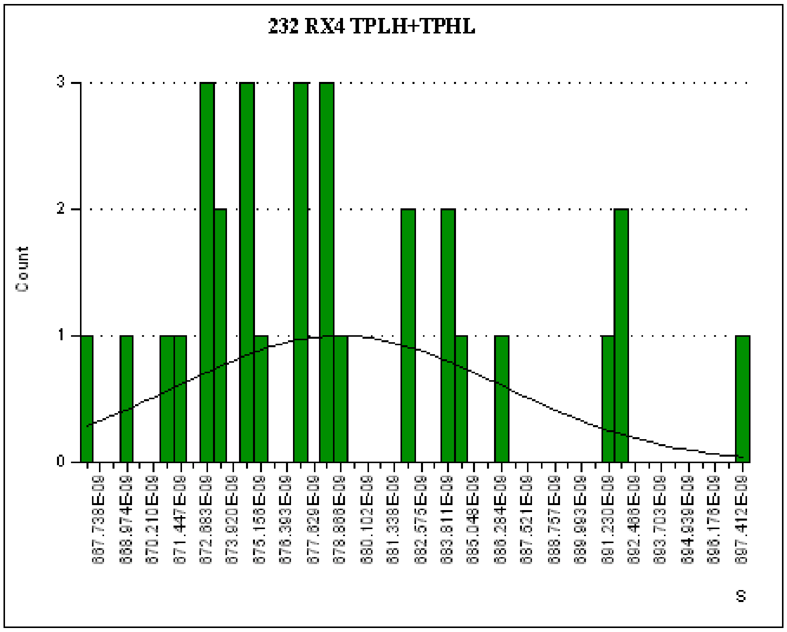
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.016, Test.Name=232 RX4 TPLH+TPHL



Statistics: (S)

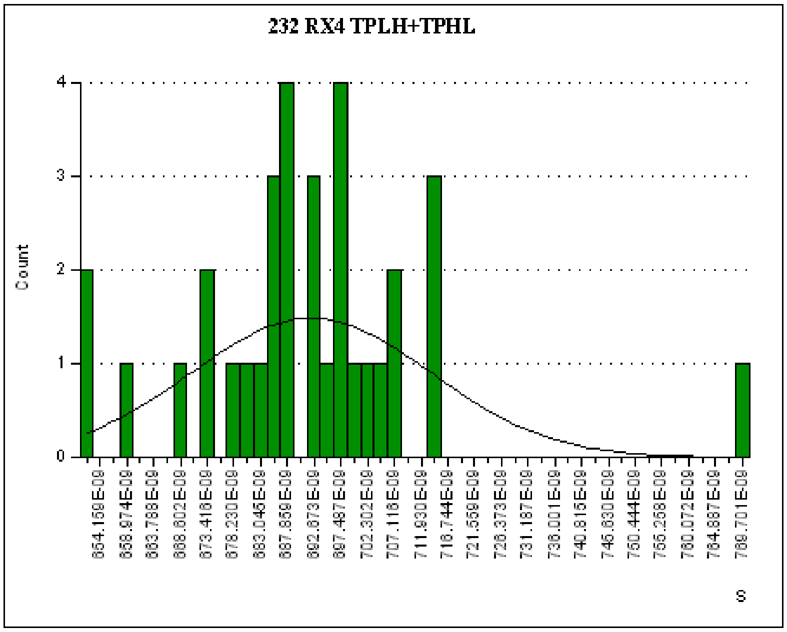
Min	667.119E-09	**Skew**	0.8528
Max	697.412E-09	**StatHigh**	N/A
Mean	678.716E-09	**StatLow**	N/A
StdDev	7.401E-09	**NWithinSpec**	N/A
25%	673.545E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	700.919E-09	**90%**	691.445E-09
		Range	30.293E-09
Mean-3*StdDev	656.514E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.016, Test.Name=232 RX4 TPLH+TPHL



Statistics: (S)

Min	651.752E-09	**StatLow**	N/A
Max	769.701E-09	**NWithinSpec**	N/A
Mean	691.692E-09	**NOutsideSpec**	N/A
StdDev	21.343E-09	**90%**	713.535E-09
25%	683.580E-09	**Range**	117.949E-09
Mean+3*StdDev	755.723E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	627.662E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.1282		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

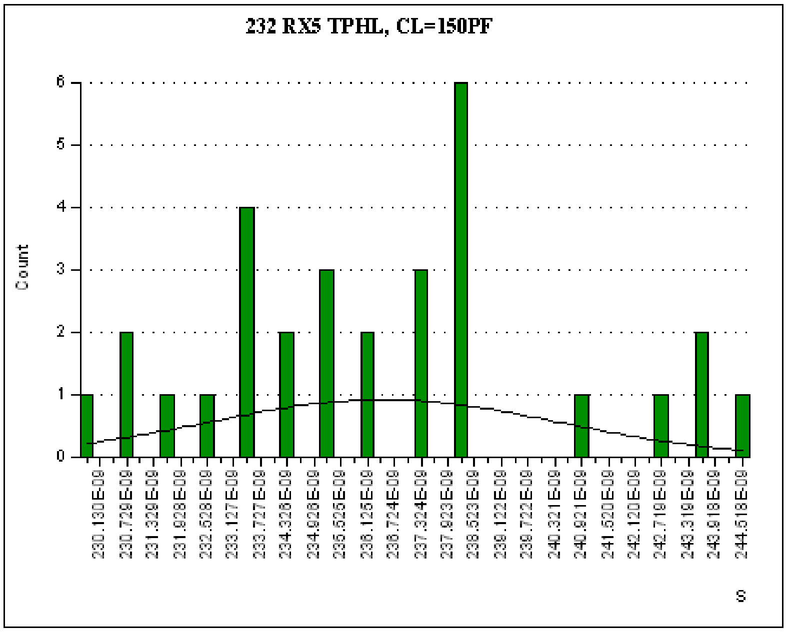
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.017, Test.Name=232 RX5 TPHL, CL=150PF



Statistics: (S)

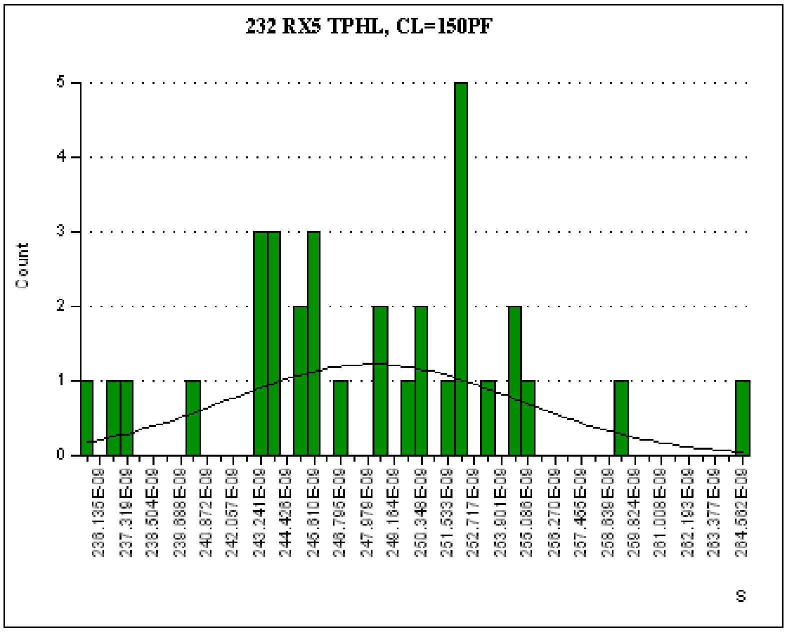
Min	229.830E-09	**Skew**	0.4509
Max	244.518E-09	**StatHigh**	N/A
Mean	236.409E-09	**StatLow**	N/A
StdDev	3.880E-09	**NWithinSpec**	N/A
25%	233.502E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	248.050E-09	**90%**	243.141E-09
		Range	14.687E-09
Mean-3*StdDev	224.768E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.017, Test.Name=232 RX5 TPHL, CL=150PF



Statistics: (S)

Min	235.542E-09	**StatLow**	N/A
Max	264.562E-09	**NWithinSpec**	N/A
Mean	248.080E-09	**NOutsideSpec**	N/A
StdDev	6.362E-09	**90%**	254.264E-09
25%	243.967E-09	**Range**	29.019E-09
Mean+3*StdDev	267.165E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	228.996E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.1658		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

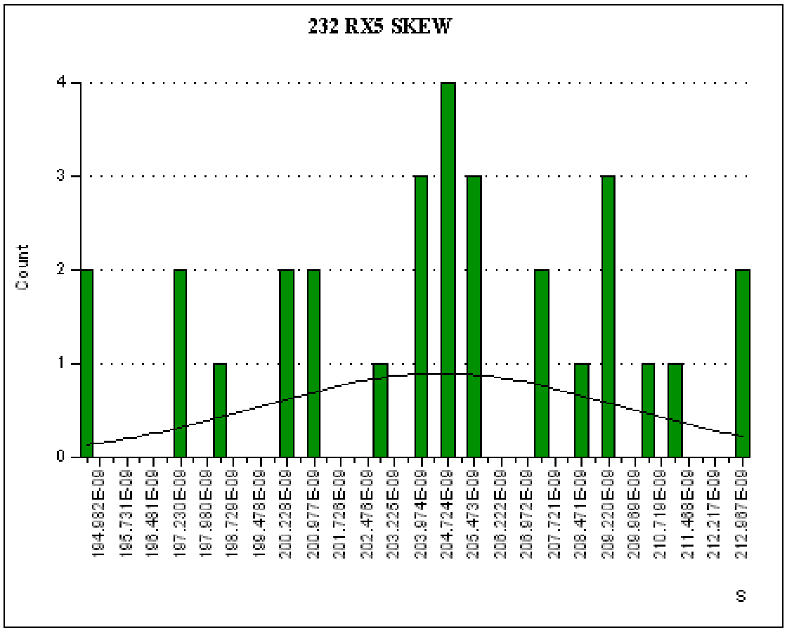
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.018, Test.Name=232 RX5 SKEW



Statistics: (S)

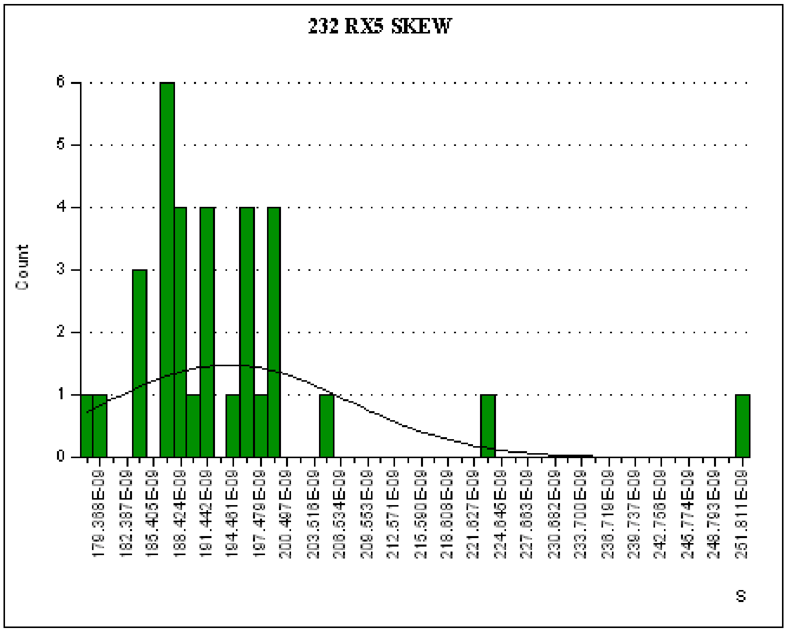
Min	194.607E-09	**Skew**	-0.2558
Max	212.967E-09	**StatHigh**	N/A
Mean	204.430E-09	**StatLow**	N/A
StdDev	5.011E-09	**NWithinSpec**	N/A
25%	201.033E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	219.464E-09	**90%**	210.672E-09
		Range	18.359E-09
Mean-3*StdDev	189.395E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.018, Test.Name=232 RX5 SKEW



Statistics: (S)

Min	177.859E-09	**StatLow**	N/A
Max	251.811E-09	**NWithinSpec**	N/A
Mean	193.744E-09	**NOutsideSpec**	N/A
StdDev	13.377E-09	**90%**	199.389E-09
25%	187.220E-09	**Range**	73.952E-09
Mean+3*StdDev	233.876E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	153.612E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.9434		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

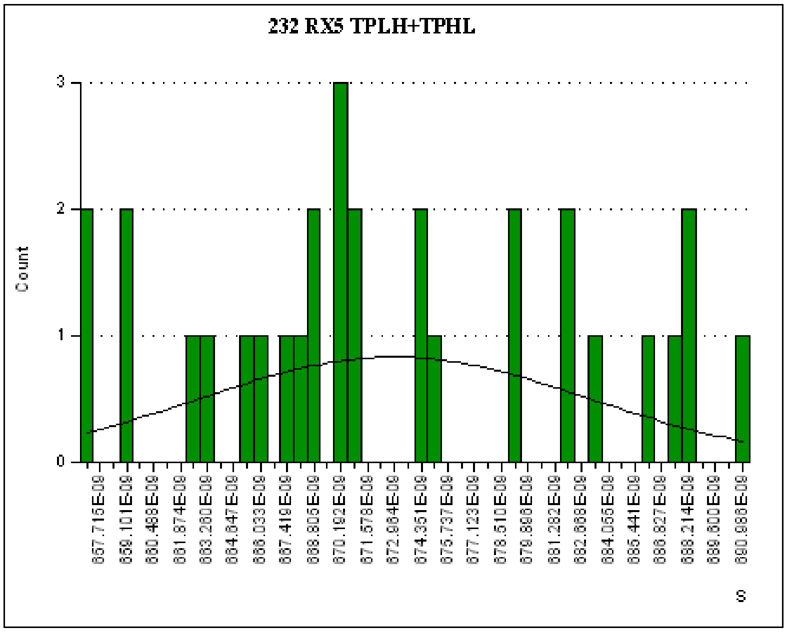
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=16.019, Test.Name=232 RX5 TPLH+TPHL



Statistics: (S)

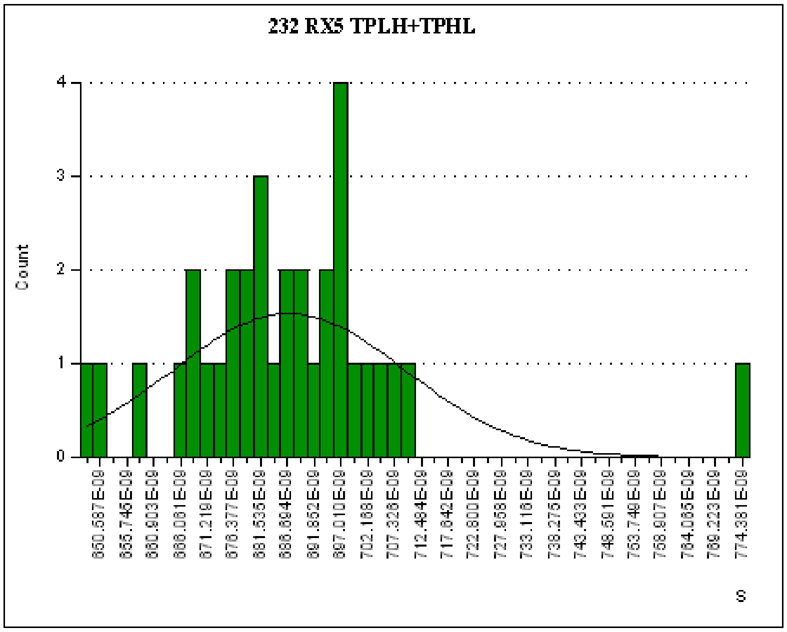
Min	657.022E-09	**Skew**	0.2142
Max	690.986E-09	**StatHigh**	N/A
Mean	672.811E-09	**StatLow**	N/A
StdDev	9.949E-09	**NWithinSpec**	N/A
25%	666.201E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	702.659E-09	**90%**	687.773E-09
		Range	33.965E-09
Mean-3*StdDev	642.962E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.019, Test.Name=232 RX5 TPLH+TPHL



Statistics: (S)

Min	648.008E-09	**StatLow**	N/A
Max	774.381E-09	**NWithinSpec**	N/A
Mean	686.558E-09	**NOutsideSpec**	N/A
StdDev	22.086E-09	**90%**	705.110E-09
25%	675.155E-09	**Range**	126.373E-09
Mean+3*StdDev	752.816E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	620.300E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.7096		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

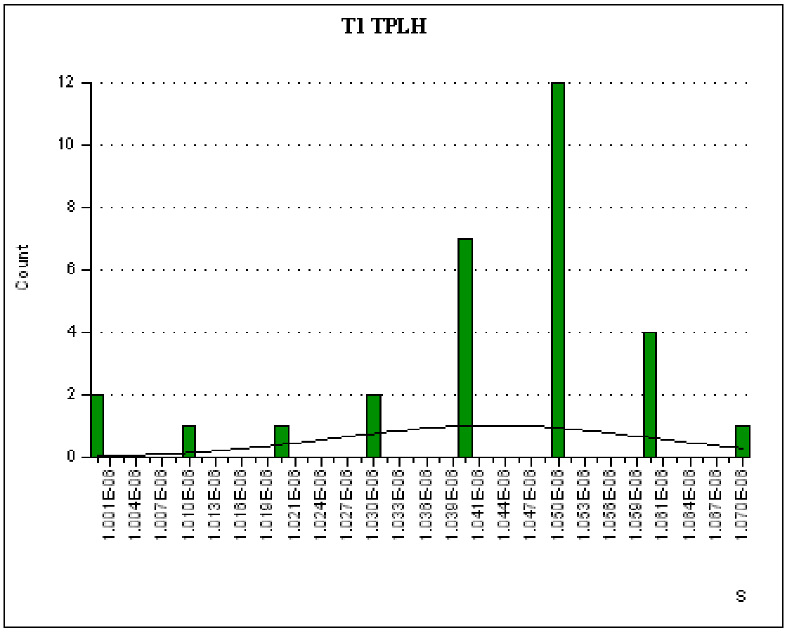
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=17.000, Test.Name=T1 TPLH



Statistics: (S)

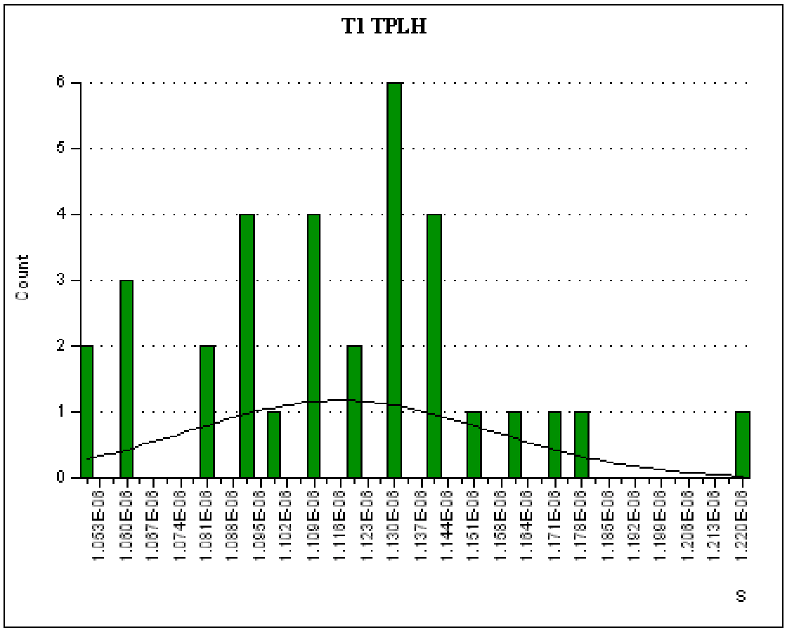
Min	999.999E-09	**Skew**	-1.2468
Max	1.070E-06	**StatHigh**	N/A
Mean	1.043E-06	**StatLow**	N/A
StdDev	16.802E-09	**NWithinSpec**	N/A
25%	1.040E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.093E-06	**90%**	1.060E-06
		Range	70.000E-09
Mean-3*StdDev	992.260E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.000, Test.Name=T1 TPLH



Statistics: (S)

Min	1.050E-06	**StatLow**	N/A
Max	1.220E-06	**NWithinSpec**	N/A
Mean	1.115E-06	**NOutsideSpec**	N/A
StdDev	38.820E-09	**90%**	1.160E-06
25%	1.090E-06	**Range**	169.999E-09
Mean+3*StdDev	1.232E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	998.690E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3373		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

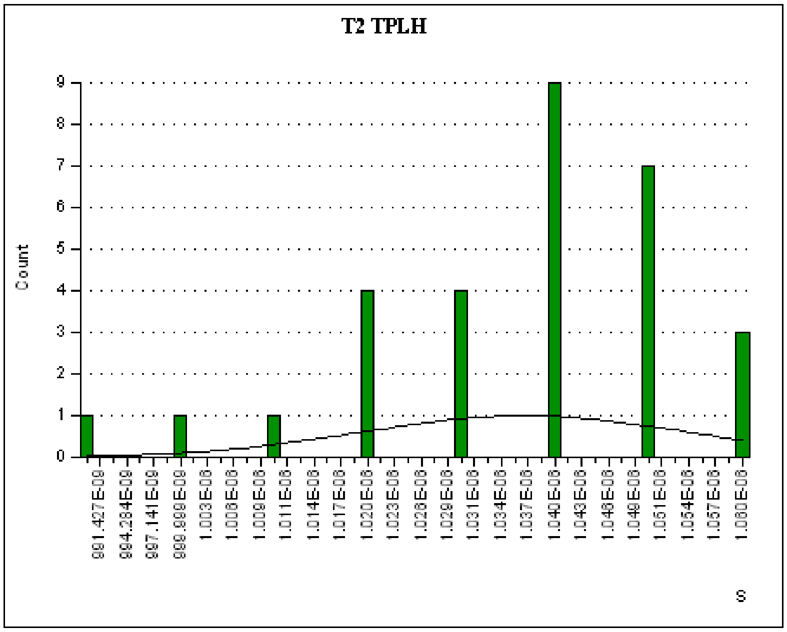
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=17.001, Test.Name=T2 TPLH



Statistics: (S)

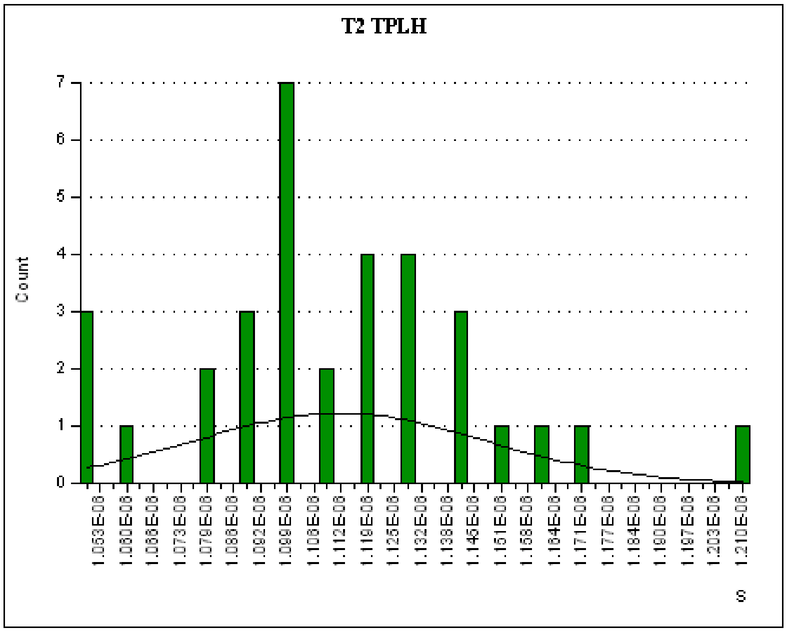
Min	989.999E-09	**Skew**	-0.9287
Max	1.060E-06	**StatHigh**	N/A
Mean	1.036E-06	**StatLow**	N/A
StdDev	17.117E-09	**NWithinSpec**	N/A
25%	1.030E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.088E-06	**90%**	1.055E-06
		Range	70.000E-09
Mean-3*StdDev	984.981E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.001, Test.Name=T2 TPLH



Statistics: (S)

Min	1.050E-06	**StatLow**	N/A
Max	1.210E-06	**NWithinSpec**	N/A
Mean	1.111E-06	**NOutsideSpec**	N/A
StdDev	35.067E-09	**90%**	1.150E-06
25%	1.090E-06	**Range**	159.999E-09
Mean+3*StdDev	1.216E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.006E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.4018		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

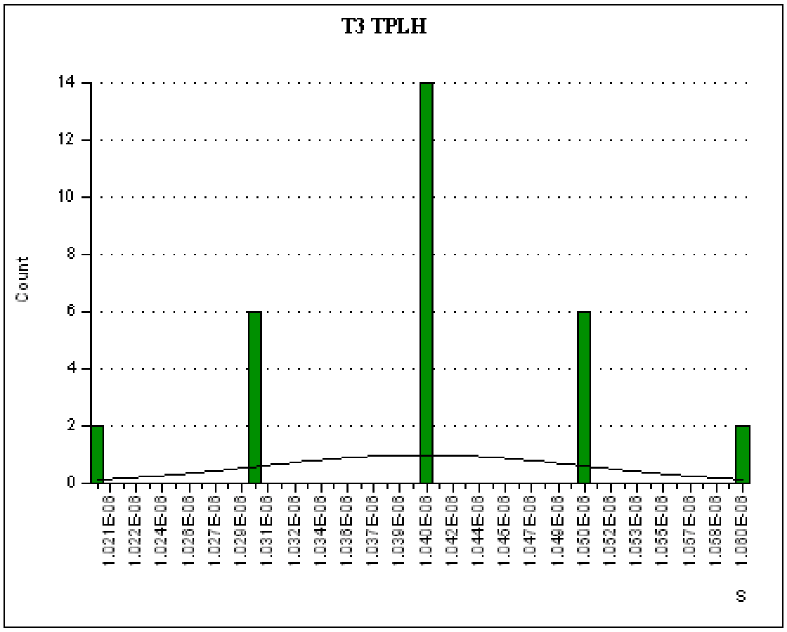
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=17.002, Test.Name=T3 TPLH



Statistics: (S)

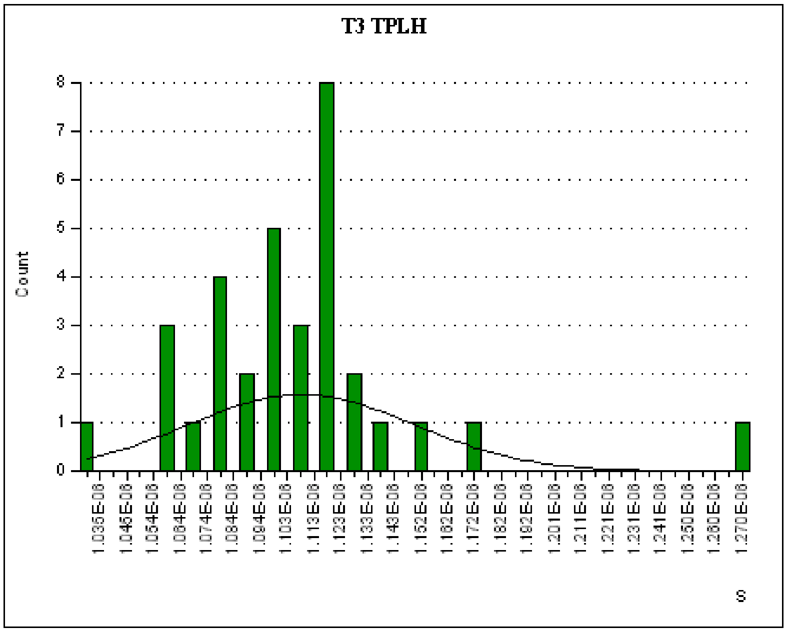
Min	1.020E-06	**Skew**	-0.0001
Max	1.060E-06	**StatHigh**	N/A
Mean	1.040E-06	**StatLow**	N/A
StdDev	9.826E-09	**NWithinSpec**	N/A
25%	1.030E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.069E-06	**90%**	1.050E-06
		Range	40.000E-09
Mean-3*StdDev	1.011E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.002, Test.Name=T3 TPLH



Statistics: (S)

Min	1.030E-06	**StatLow**	N/A
Max	1.270E-06	**NWithinSpec**	N/A
Mean	1.108E-06	**NOutsideSpec**	N/A
StdDev	40.908E-09	**90%**	1.140E-06
25%	1.080E-06	**Range**	240.000E-09
Mean+3*StdDev	1.231E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	985.153E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.7922		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

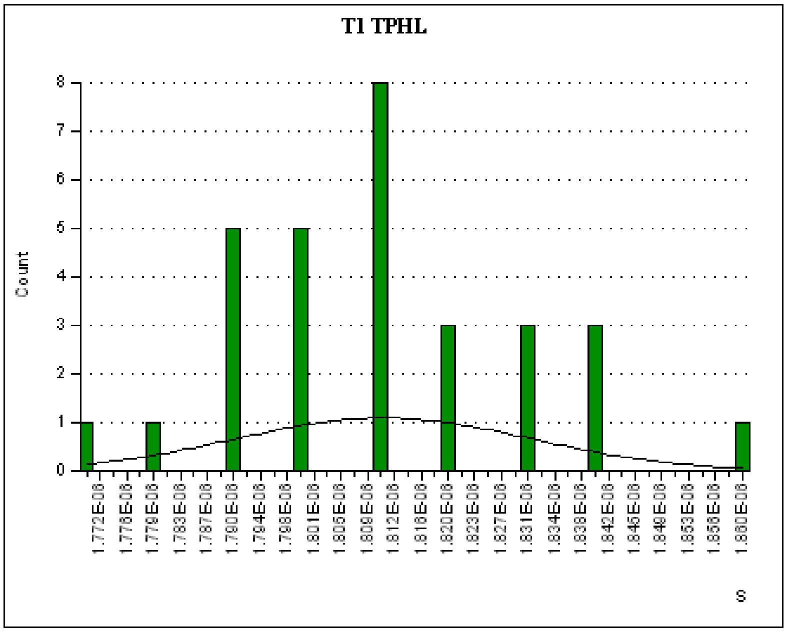
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=17.003, Test.Name=T1 TPHL



Statistics: (S)

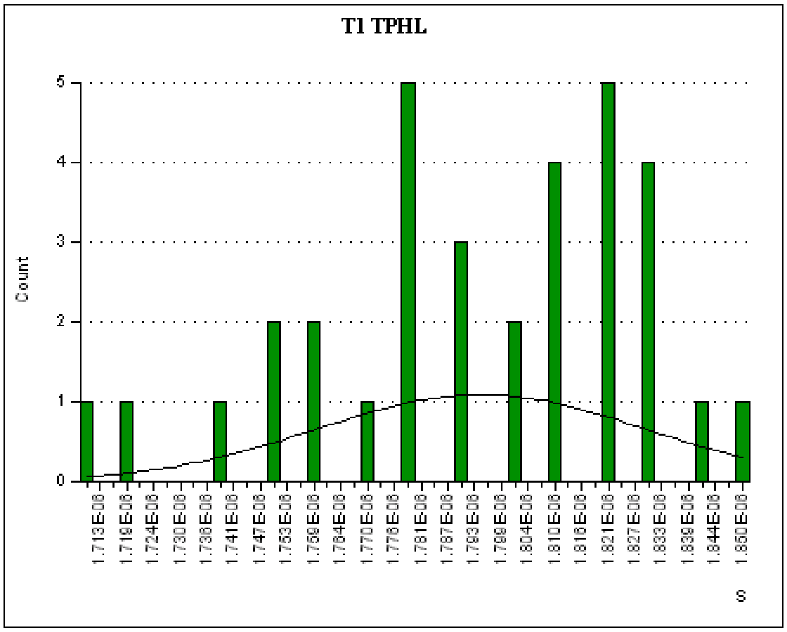
Min	1.770E-06	**Skew**	0.3891
Max	1.860E-06	**StatHigh**	N/A
Mean	1.810E-06	**StatLow**	N/A
StdDev	20.083E-09	**NWithinSpec**	N/A
25%	1.800E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.871E-06	**90%**	1.840E-06
		Range	90.000E-09
Mean-3*StdDev	1.750E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.003, Test.Name=T1 TPHL



Statistics: (S)

Min	1.710E-06	**StatLow**	N/A
Max	1.850E-06	**NWithinSpec**	N/A
Mean	1.793E-06	**NOutsideSpec**	N/A
StdDev	34.521E-09	**90%**	1.830E-06
25%	1.780E-06	**Range**	139.999E-09
Mean+3*StdDev	1.897E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.690E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.6401		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

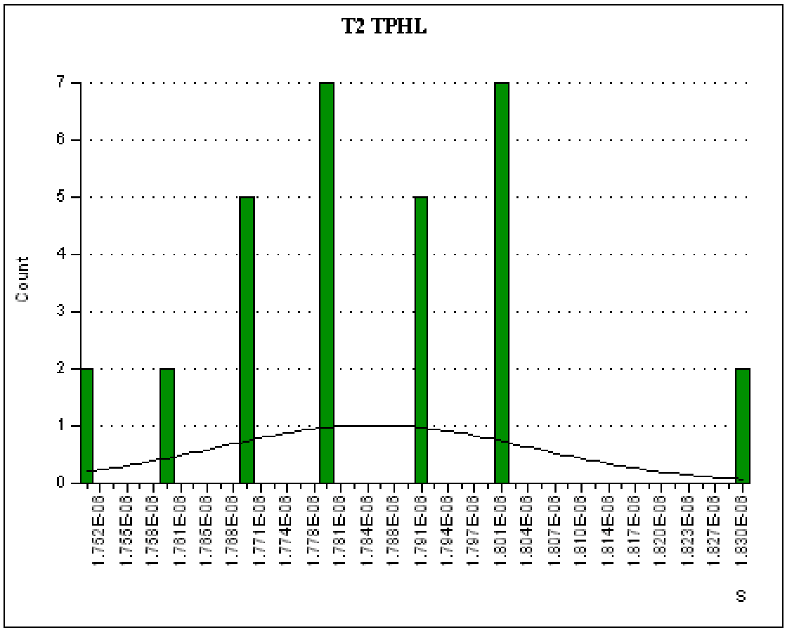
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=17.005, Test.Name=T2 TPHL



Statistics: (S)

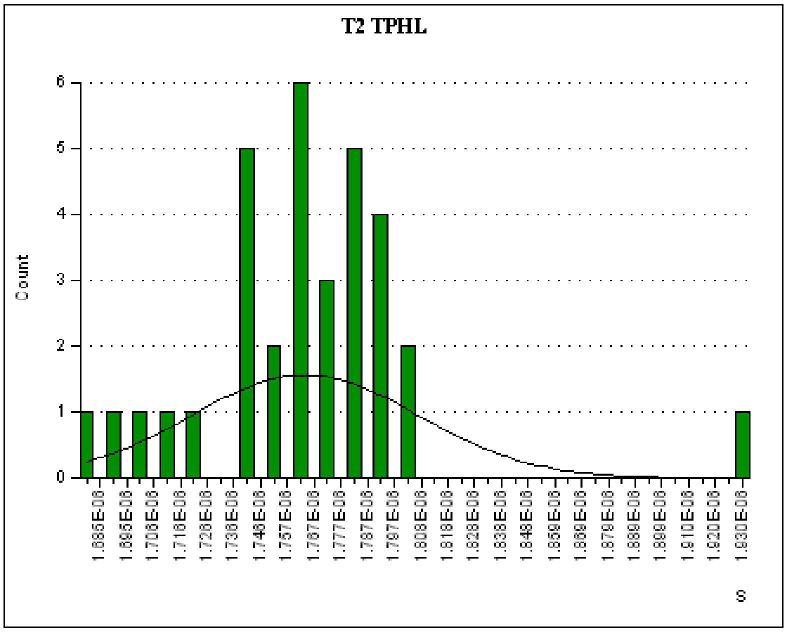
Min	1.750E-06	**Skew**	0.4272
Max	1.830E-06	**StatHigh**	N/A
Mean	1.785E-06	**StatLow**	N/A
StdDev	19.250E-09	**NWithinSpec**	N/A
25%	1.770E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.842E-06	**90%**	1.800E-06
		Range	80.000E-09
Mean-3*StdDev	1.727E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.005, Test.Name=T2 TPHL



Statistics: (S)

Min	1.680E-06	**StatLow**	N/A
Max	1.930E-06	**NWithinSpec**	N/A
Mean	1.762E-06	**NOutsideSpec**	N/A
StdDev	42.941E-09	**90%**	1.790E-06
25%	1.740E-06	**Range**	250.000E-09
Mean+3*StdDev	1.891E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.634E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.4538		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

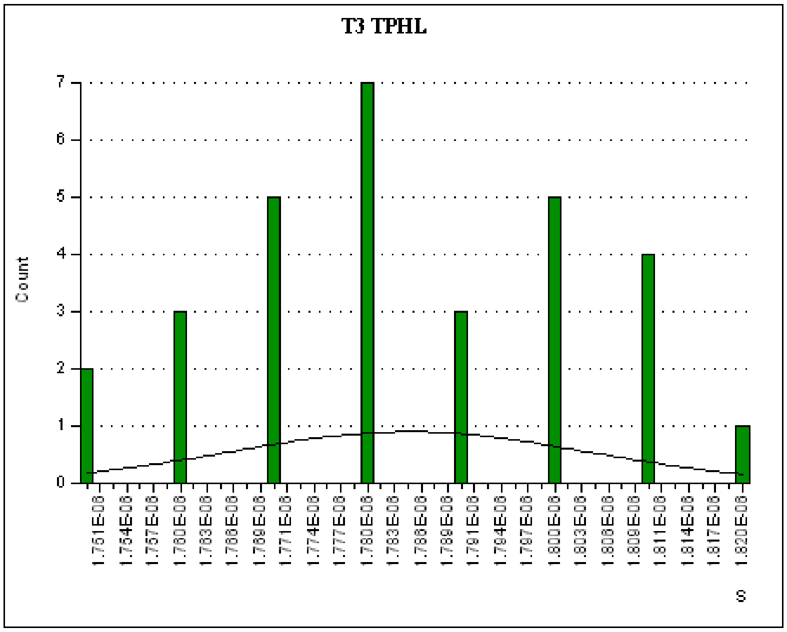
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=17.007, Test.Name=T3 TPHL



Statistics: (S)

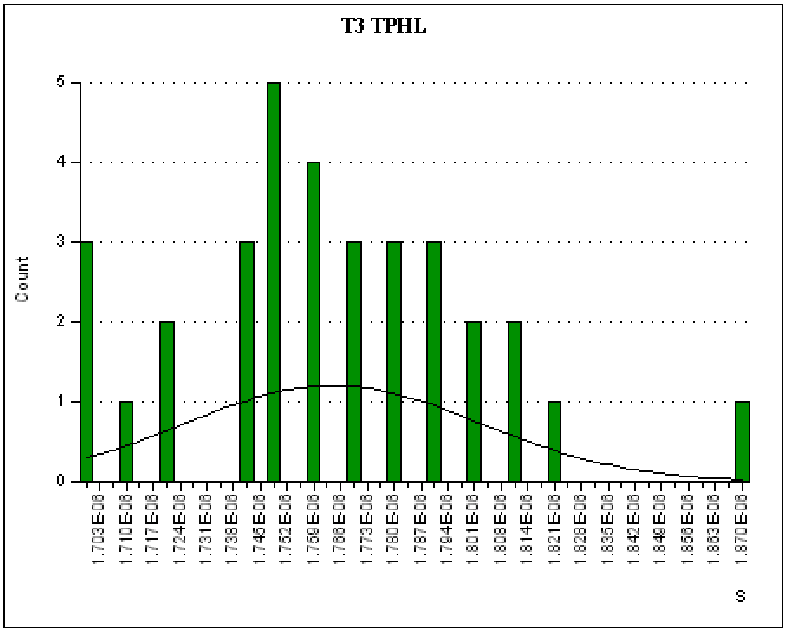
Min	1.750E-06	**Skew**	0.0205
Max	1.820E-06	**StatHigh**	N/A
Mean	1.784E-06	**StatLow**	N/A
StdDev	19.046E-09	**NWithinSpec**	N/A
25%	1.770E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.841E-06	**90%**	1.810E-06
		Range	70.000E-09
Mean-3*StdDev	1.727E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.007, Test.Name=T3 TPHL



Statistics: (S)

Min	1.700E-06	**StatLow**	N/A
Max	1.870E-06	**NWithinSpec**	N/A
Mean	1.763E-06	**NOutsideSpec**	N/A
StdDev	37.887E-09	**90%**	1.810E-06
25%	1.740E-06	**Range**	169.999E-09
Mean+3*StdDev	1.877E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.650E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3930		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

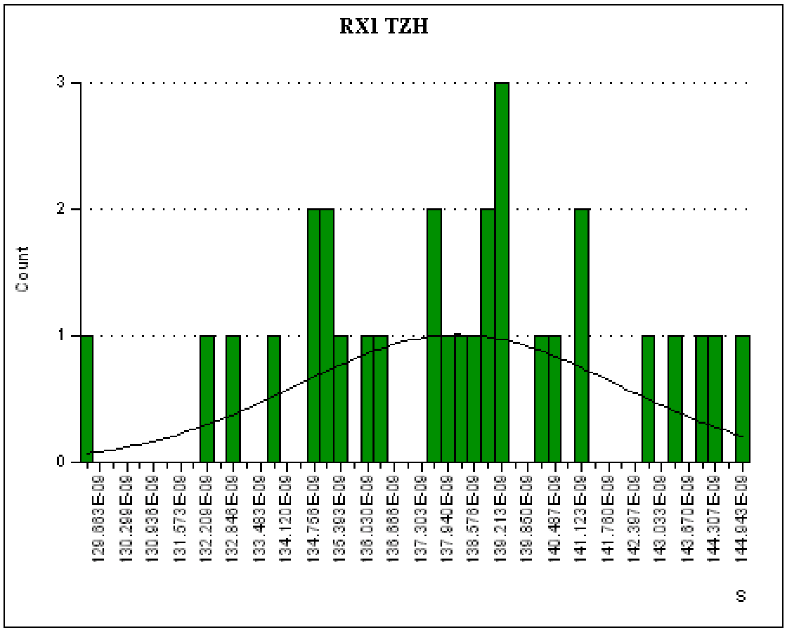
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.000, Test.Name=RX1 TZH



Statistics: (S)

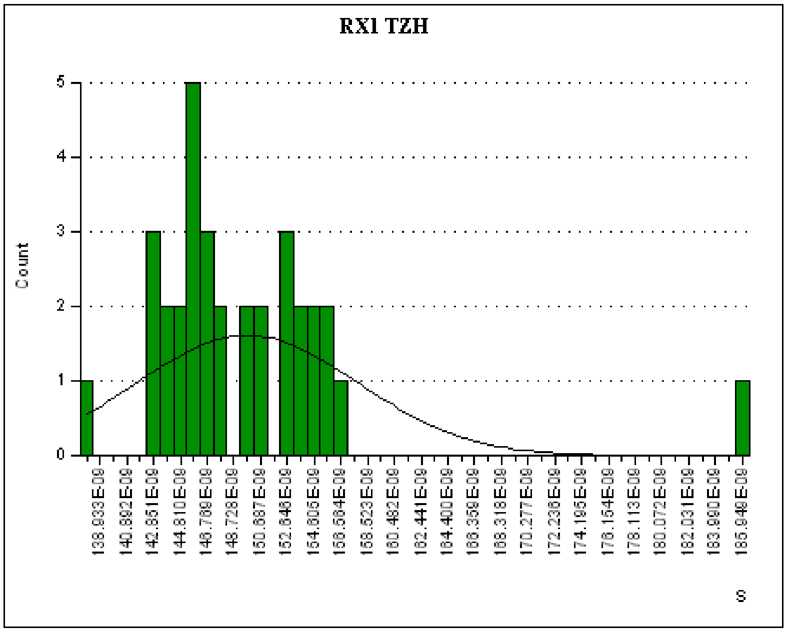
Min	129.344E-09	**Skew**	-0.1349
Max	144.943E-09	**StatHigh**	N/A
Mean	138.082E-09	**StatLow**	N/A
StdDev	3.783E-09	**NWithinSpec**	N/A
25%	135.109E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	149.432E-09	**90%**	143.587E-09
		Range	15.599E-09
Mean-3*StdDev	126.732E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.000, Test.Name=RX1 TZH



Statistics: (S)

Min	137.954E-09	**StatLow**	N/A
Max	185.949E-09	**NWithinSpec**	N/A
Mean	149.589E-09	**NOutsideSpec**	N/A
StdDev	8.000E-09	**90%**	155.563E-09
25%	145.550E-09	**Range**	47.995E-09
Mean+3*StdDev	173.590E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	125.588E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.9723		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

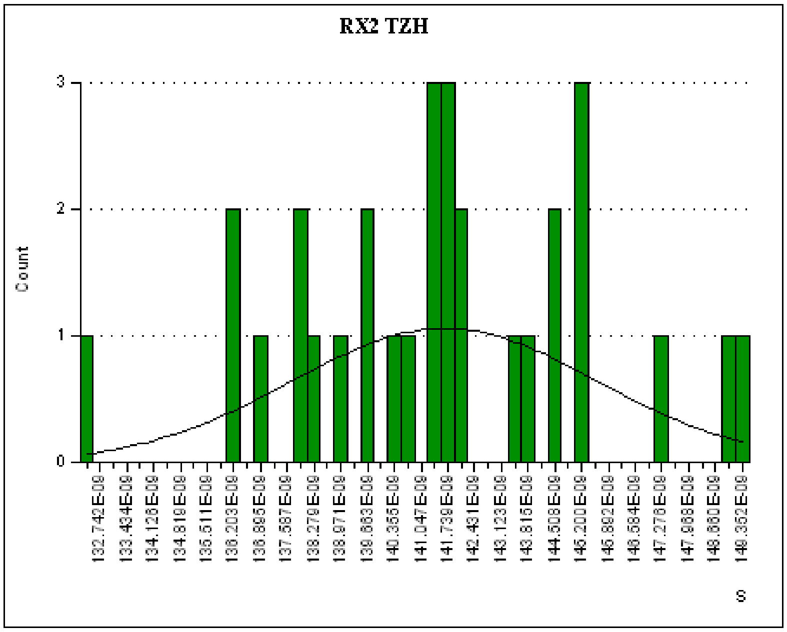
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.001, Test.Name=RX2 TZH



Statistics: (S)

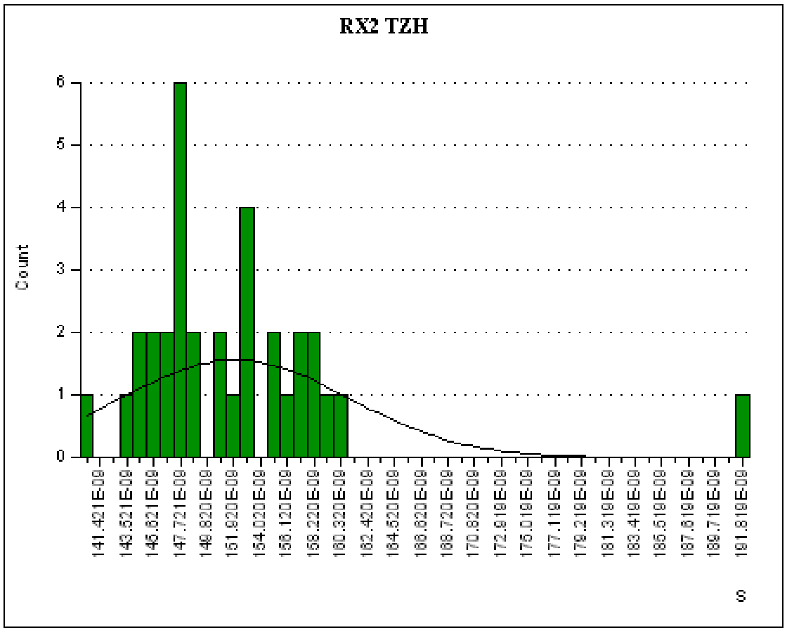
Min	132.396E-09	**Skew**	-0.0467
Max	149.352E-09	**StatHigh**	N/A
Mean	141.564E-09	**StatLow**	N/A
StdDev	3.914E-09	**NWithinSpec**	N/A
25%	138.839E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	153.305E-09	**90%**	146.300E-09
		Range	16.956E-09
Mean-3*StdDev	129.822E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.001, Test.Name=RX2 TZH



Statistics: (S)

Min	140.371E-09	**StatLow**	N/A
Max	191.819E-09	**NWithinSpec**	N/A
Mean	151.912E-09	**NOutsideSpec**	N/A
StdDev	8.837E-09	**90%**	157.981E-09
25%	147.277E-09	**Range**	51.448E-09
Mean+3*StdDev	178.424E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	125.400E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.9456		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

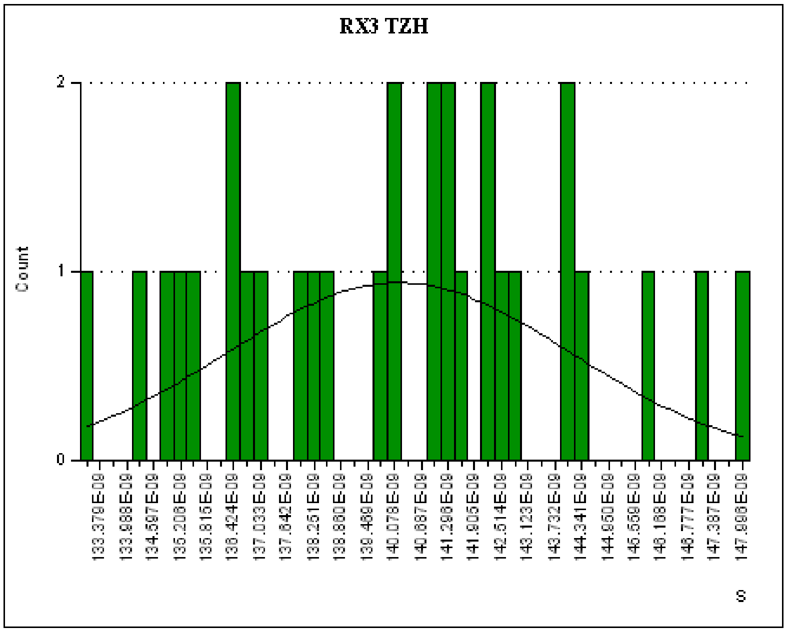
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.002, Test.Name=RX3 TZH



Statistics: (S)

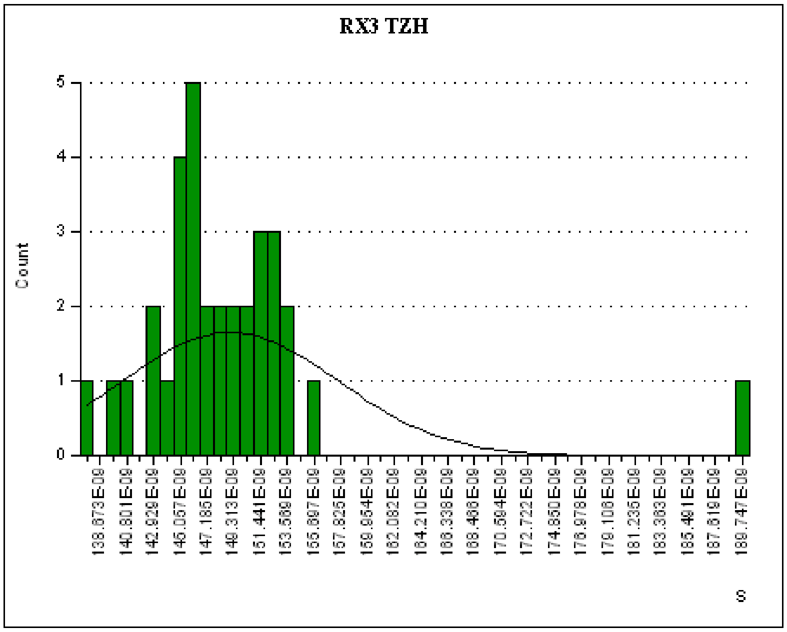
Min	133.074E-09	**Skew**	0.1107
Max	147.996E-09	**StatHigh**	N/A
Mean	140.105E-09	**StatLow**	N/A
StdDev	3.866E-09	**NWithinSpec**	N/A
25%	136.805E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	151.705E-09	**90%**	145.113E-09
		Range	14.921E-09
Mean-3*StdDev	128.506E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.002, Test.Name=RX3 TZH



Statistics: (S)

Min	137.609E-09	**StatLow**	N/A
Max	189.747E-09	**NWithinSpec**	N/A
Mean	148.898E-09	**NOutsideSpec**	N/A
StdDev	8.485E-09	**90%**	153.492E-09
25%	145.205E-09	**Range**	52.138E-09
Mean+3*StdDev	174.354E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	123.443E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.5571		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

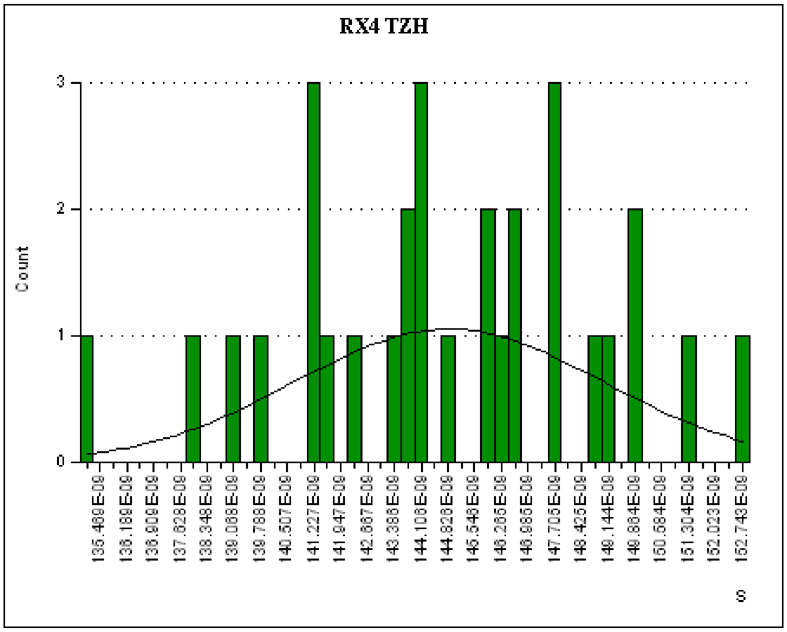
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.003, Test.Name=RX4 TZH



Statistics: (S)

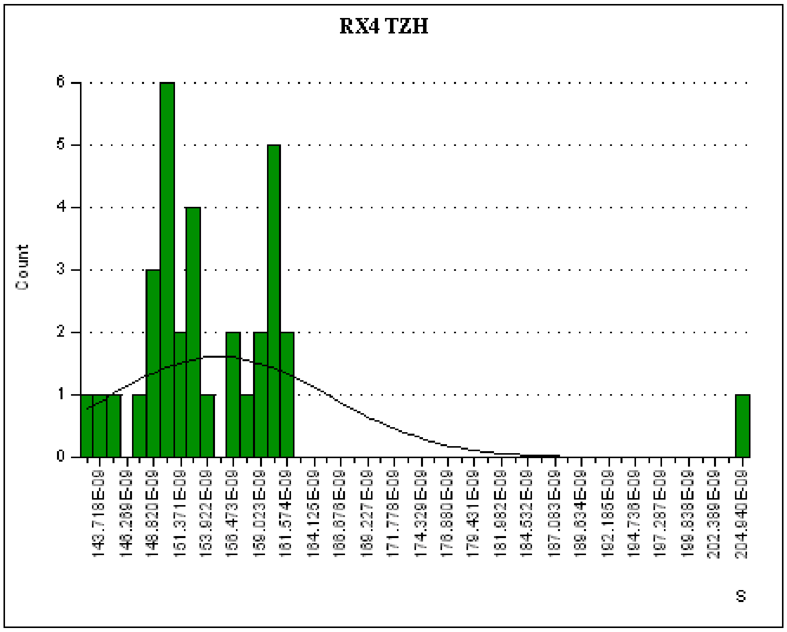
Min	135.109E-09	**Skew**	-0.2042
Max	152.743E-09	**StatHigh**	N/A
Mean	144.763E-09	**StatLow**	N/A
StdDev	4.086E-09	**NWithinSpec**	N/A
25%	141.552E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	157.020E-09	**90%**	149.861E-09
		Range	17.634E-09
Mean-3*StdDev	132.506E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.003, Test.Name=RX4 TZH



Statistics: (S)

Min	142.443E-09	**StatLow**	N/A
Max	204.940E-09	**NWithinSpec**	N/A
Mean	154.957E-09	**NOutsideSpec**	N/A
StdDev	10.420E-09	**90%**	160.743E-09
25%	150.039E-09	**Range**	62.497E-09
Mean+3*StdDev	186.215E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	123.698E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.5380		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

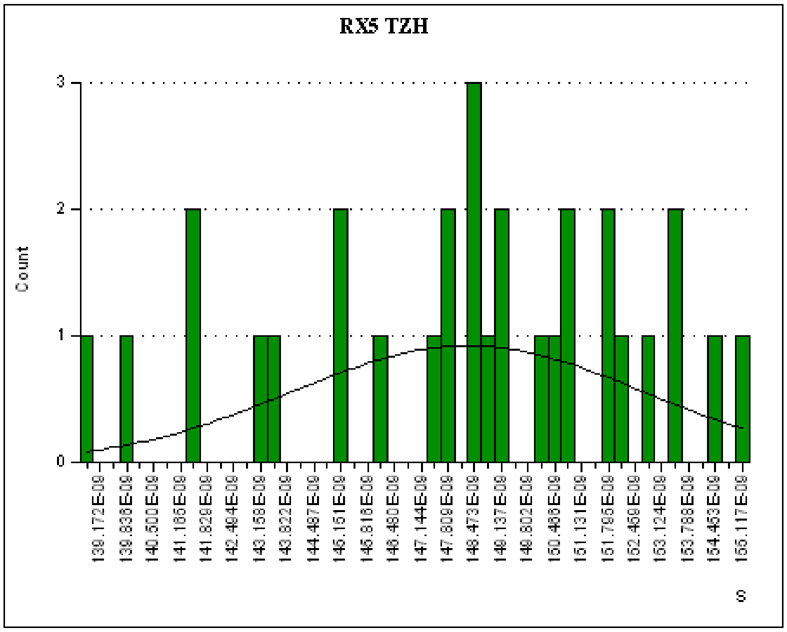
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.004, Test.Name=RX5 TZH



Statistics: (S)

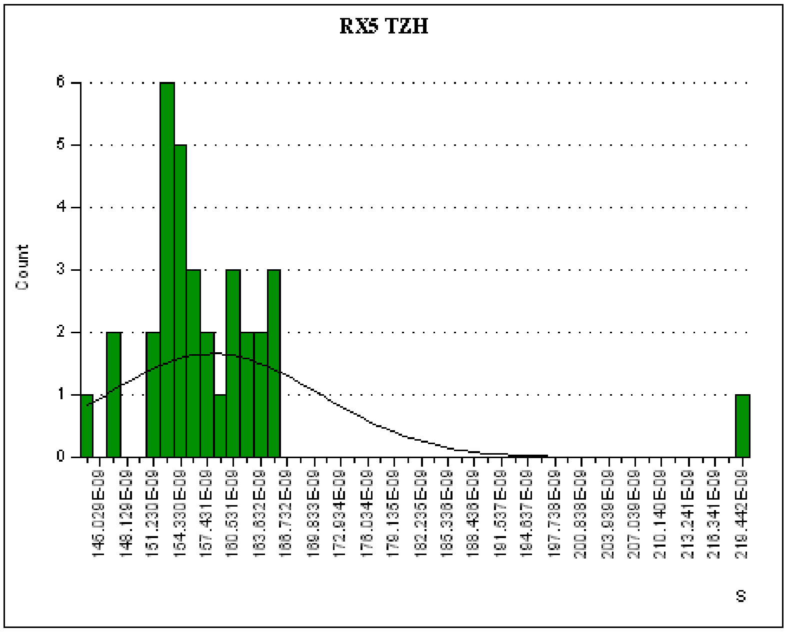
Min	138.839E-09	**Skew**	-0.5259
Max	155.117E-09	**StatHigh**	N/A
Mean	148.210E-09	**StatLow**	N/A
StdDev	4.305E-09	**NWithinSpec**	N/A
25%	145.283E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	161.124E-09	**90%**	153.421E-09
		Range	16.278E-09
Mean-3*StdDev	135.296E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.004, Test.Name=RX5 TZH



Statistics: (S)

Min	143.478E-09	**StatLow**	N/A
Max	219.442E-09	**NWithinSpec**	N/A
Mean	157.991E-09	**NOutsideSpec**	N/A
StdDev	12.328E-09	**90%**	164.541E-09
25%	152.456E-09	**Range**	75.963E-09
Mean+3*StdDev	194.974E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	121.008E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	4.0025		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

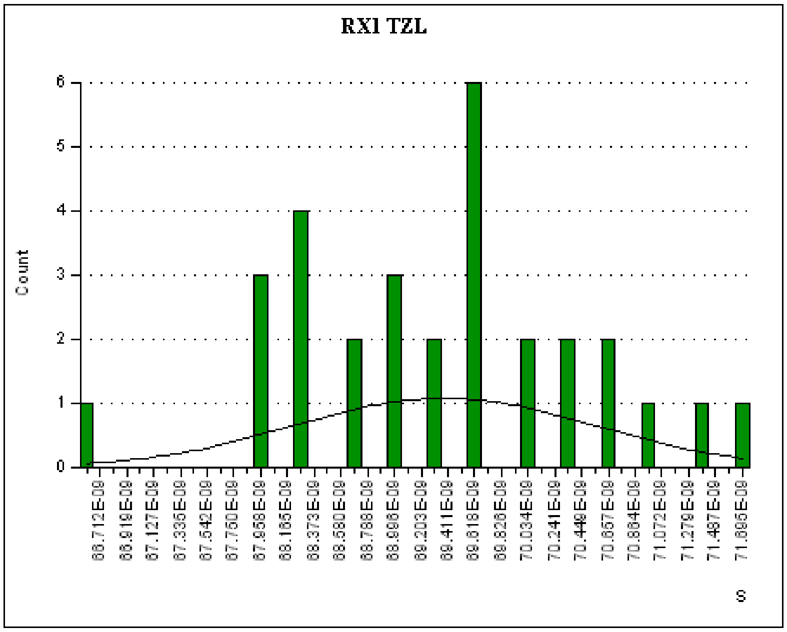
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.005, Test.Name=RX1 TZL



Statistics: (S)

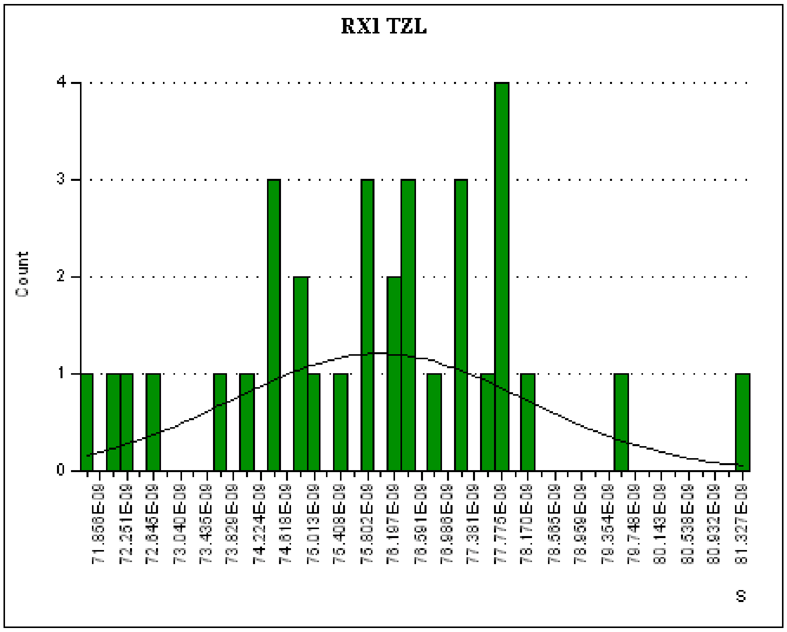
Min	66.608E-09	**Skew**	-0.0407
Max	71.695E-09	**StatHigh**	N/A
Mean	69.355E-09	**StatLow**	N/A
StdDev	1.149E-09	**NWithinSpec**	N/A
25%	68.304E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	72.801E-09	**90%**	70.847E-09
		Range	5.087E-09
Mean-3*StdDev	65.909E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.005, Test.Name=RX1 TZL



Statistics: (S)

Min	71.659E-09	**StatLow**	N/A
Max	81.327E-09	**NWithinSpec**	N/A
Mean	75.928E-09	**NOutsideSpec**	N/A
StdDev	2.149E-09	**90%**	77.874E-09
25%	74.421E-09	**Range**	9.668E-09
Mean+3*StdDev	82.375E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	69.481E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0367		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

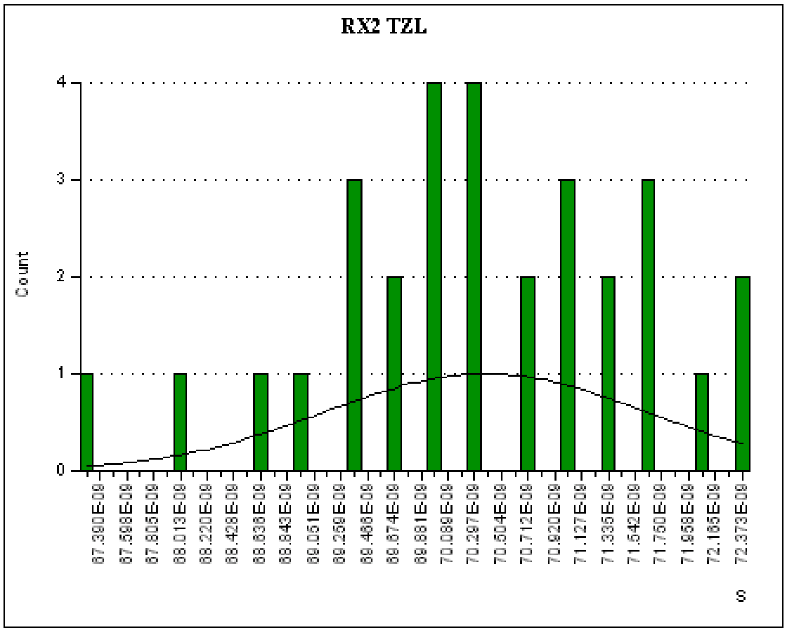
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.006, Test.Name=RX2 TZL



Statistics: (S)

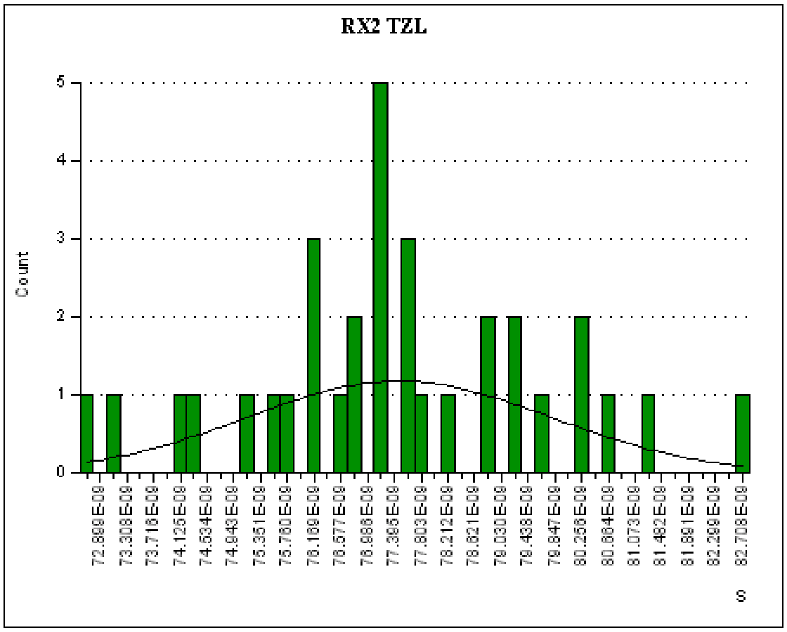
Min	67.286E-09	**Skew**	-0.4333
Max	72.373E-09	**StatHigh**	N/A
Mean	70.350E-09	**StatLow**	N/A
StdDev	1.239E-09	**NWithinSpec**	N/A
25%	69.660E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	74.066E-09	**90%**	71.864E-09
		Range	5.087E-09
Mean-3*StdDev	66.633E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.006, Test.Name=RX2 TZL



Statistics: (S)

Min	72.695E-09	**StatLow**	N/A
Max	82.708E-09	**NWithinSpec**	N/A
Mean	77.424E-09	**NOutsideSpec**	N/A
StdDev	2.285E-09	**90%**	80.291E-09
25%	76.148E-09	**Range**	10.013E-09
Mean+3*StdDev	84.278E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	70.570E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0853		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

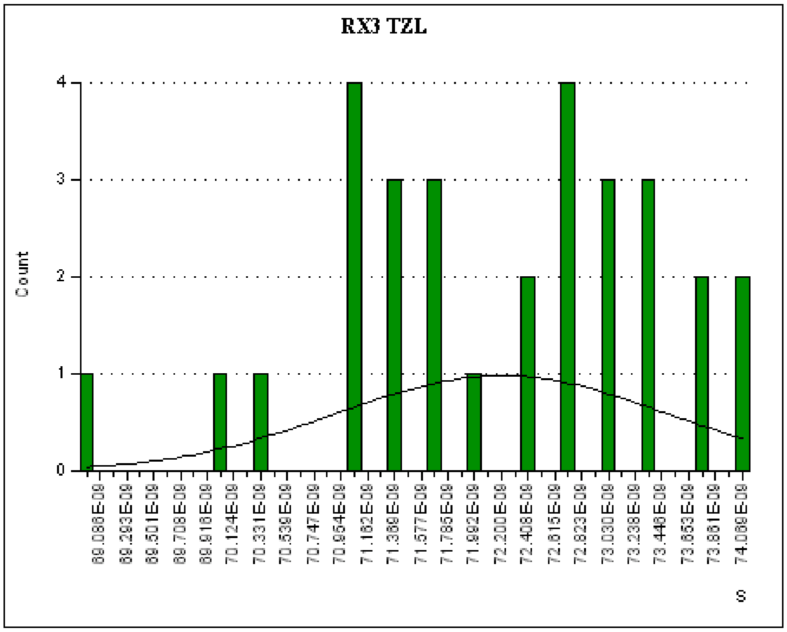
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.007, Test.Name=RX3 TZL



Statistics: (S)

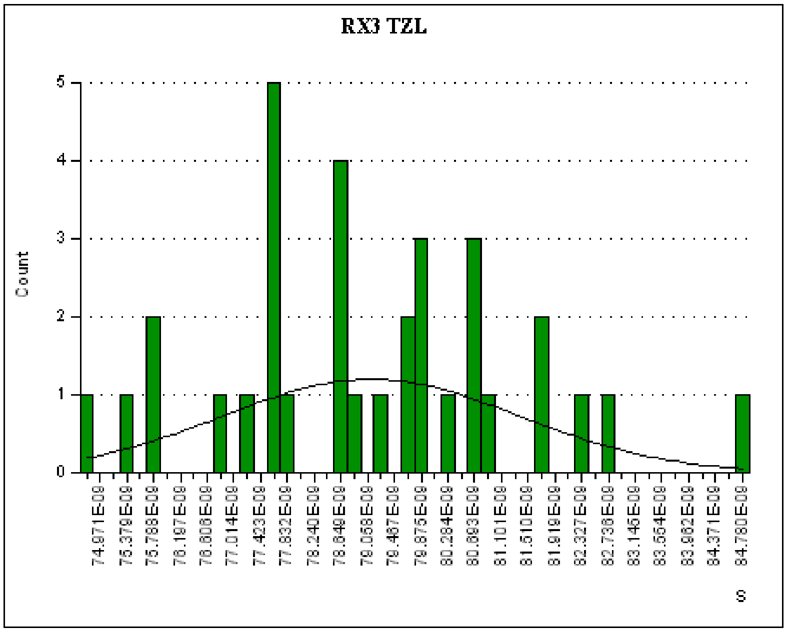
Min	68.982E-09	**Skew**	-0.5001
Max	74.069E-09	**StatHigh**	N/A
Mean	72.169E-09	**StatLow**	N/A
StdDev	1.264E-09	**NWithinSpec**	N/A
25%	71.356E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	75.963E-09	**90%**	73.729E-09
		Range	5.087E-09
Mean-3*StdDev	68.376E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.007, Test.Name=RX3 TZL



Statistics: (S)

Min	74.766E-09	**StatLow**	N/A
Max	84.780E-09	**NWithinSpec**	N/A
Mean	79.067E-09	**NOutsideSpec**	N/A
StdDev	2.246E-09	**90%**	81.672E-09
25%	77.529E-09	**Range**	10.013E-09
Mean+3*StdDev	85.805E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	72.328E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2771		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

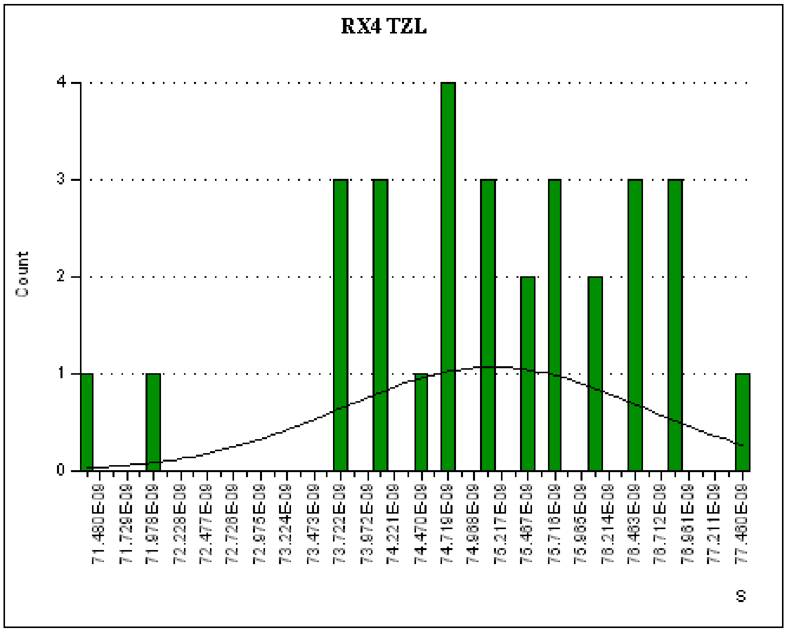
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.008, Test.Name=RX4 TZL



Statistics: (S)

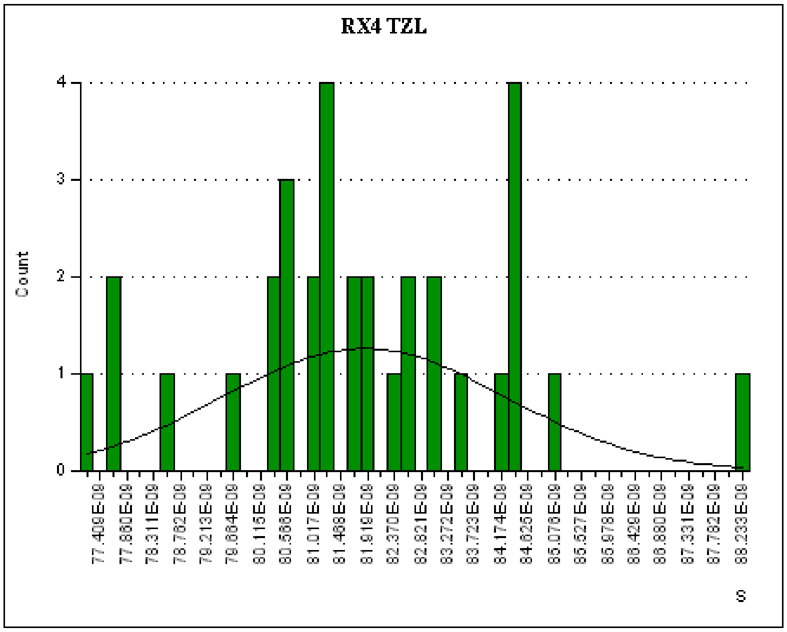
Min	71.356E-09	**Skew**	-0.7492
Max	77.460E-09	**StatHigh**	N/A
Mean	75.097E-09	**StatLow**	N/A
StdDev	1.392E-09	**NWithinSpec**	N/A
25%	74.069E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	79.275E-09	**90%**	76.781E-09
		Range	6.104E-09
Mean-3*StdDev	70.920E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.008, Test.Name=RX4 TZL



Statistics: (S)

Min	77.183E-09	**StatLow**	N/A
Max	88.233E-09	**NWithinSpec**	N/A
Mean	81.819E-09	**NOutsideSpec**	N/A
StdDev	2.353E-09	**90%**	84.434E-09
25%	80.636E-09	**Range**	11.049E-09
Mean+3*StdDev	88.878E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	74.760E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.1941		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

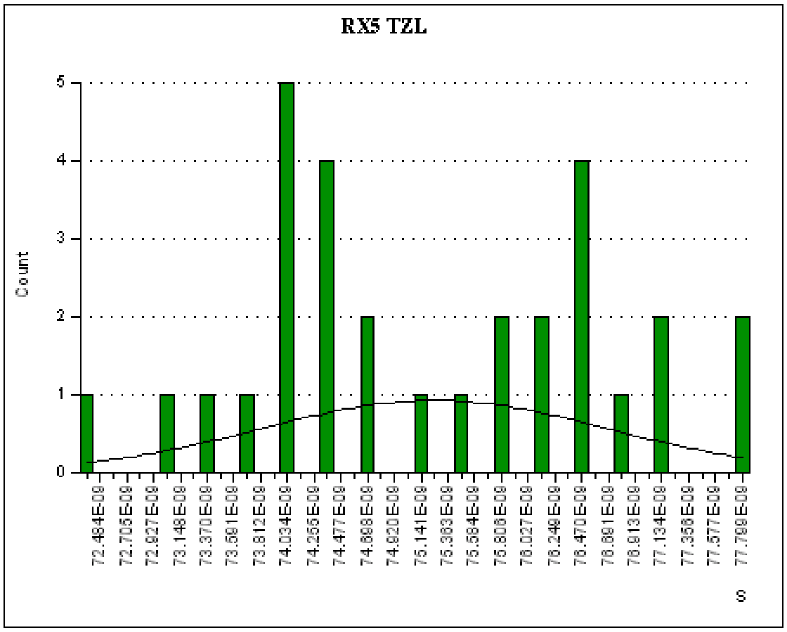
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.009, Test.Name=RX5 TZL



Statistics: (S)

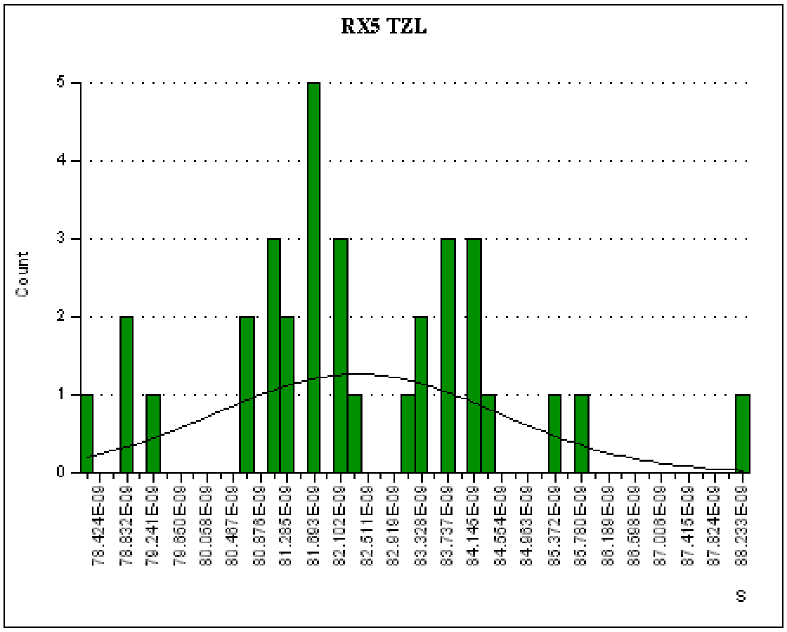
Min	72.373E-09	**Skew**	0.0996
Max	77.799E-09	**StatHigh**	N/A
Mean	75.221E-09	**StatLow**	N/A
StdDev	1.429E-09	**NWithinSpec**	N/A
25%	74.069E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	79.510E-09	**90%**	77.121E-09
		Range	5.426E-09
Mean-3*StdDev	70.933E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.009, Test.Name=RX5 TZL



Statistics: (S)

Min	78.219E-09	**StatLow**	N/A
Max	88.233E-09	**NWithinSpec**	N/A
Mean	82.310E-09	**NOutsideSpec**	N/A
StdDev	2.127E-09	**90%**	84.434E-09
25%	80.982E-09	**Range**	10.013E-09
Mean+3*StdDev	88.691E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	75.930E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.4331		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

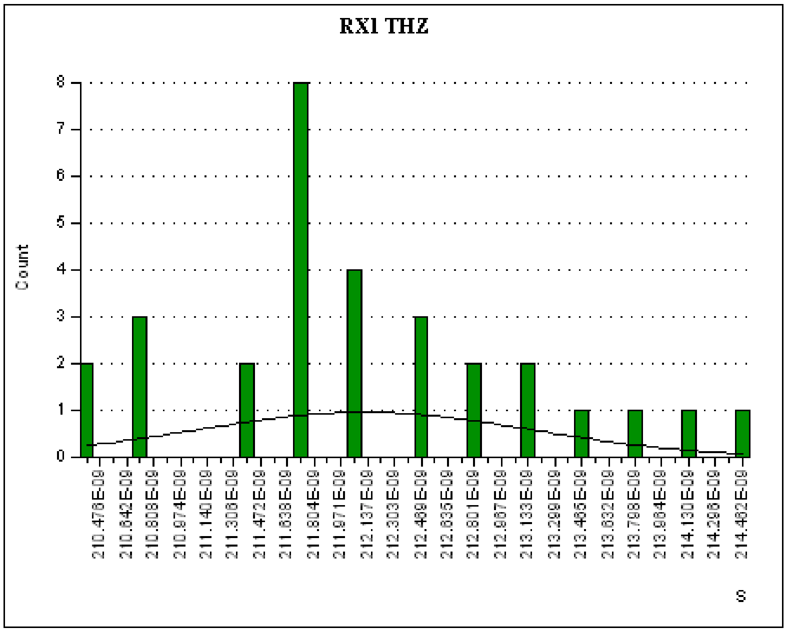
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.010, Test.Name=RX1 THZ



Statistics: (S)

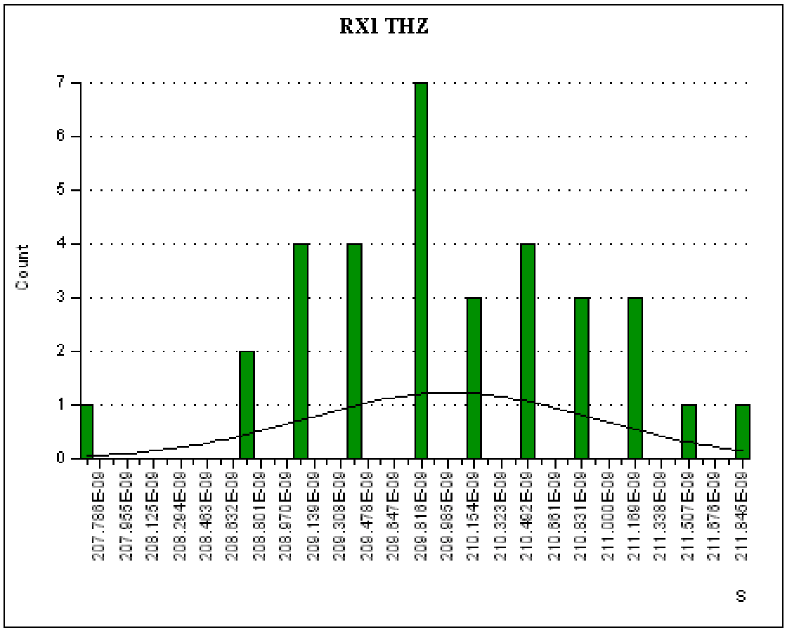
Min	210.393E-09	**Skew**	0.4292
Max	214.462E-09	**StatHigh**	N/A
Mean	212.100E-09	**StatLow**	N/A
StdDev	1.033E-09	**NWithinSpec**	N/A
25%	211.749E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	215.198E-09	**90%**	213.614E-09
		Range	4.069E-09
Mean-3*StdDev	209.001E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.010, Test.Name=RX1 THZ



Statistics: (S)

Min	207.702E-09	**StatLow**	N/A
Max	211.845E-09	**NWithinSpec**	N/A
Mean	209.972E-09	**NOutsideSpec**	N/A
StdDev	901.350E-12	**90%**	211.155E-09
25%	209.428E-09	**Range**	4.143E-09
Mean+3*StdDev	212.676E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	207.268E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0747		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

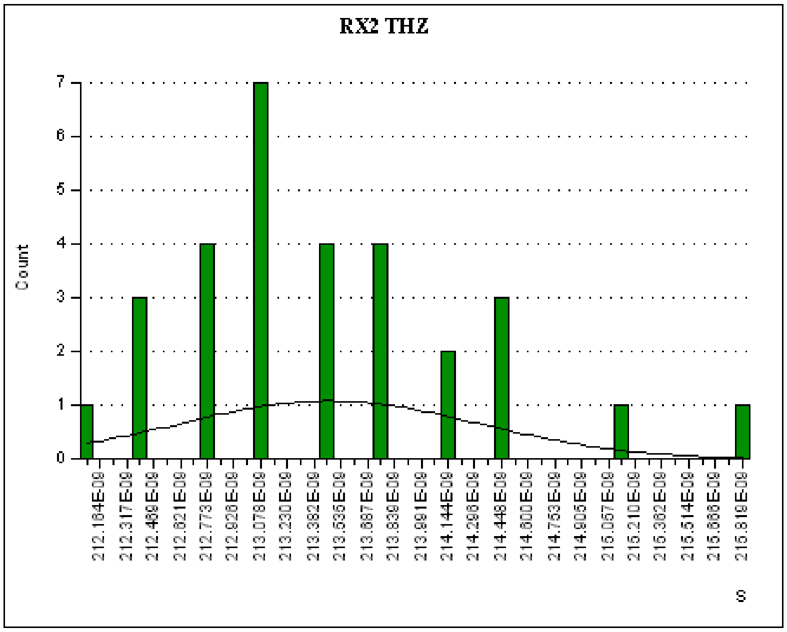
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.011, Test.Name=RX2 THZ



Statistics: (S)

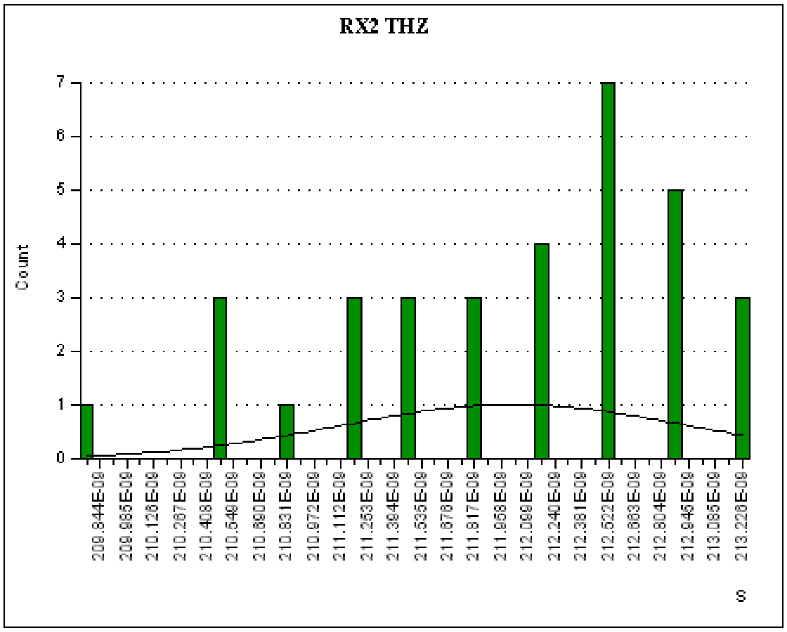
Min	212.088E-09	**Skew**	0.8847
Max	215.819E-09	**StatHigh**	N/A
Mean	213.456E-09	**StatLow**	N/A
StdDev	842.429E-12	**NWithinSpec**	N/A
25%	212.767E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	215.983E-09	**90%**	214.462E-09
		Range	3.730E-09
Mean-3*StdDev	210.929E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.011, Test.Name=RX2 THZ



Statistics: (S)

Min	209.774E-09	**StatLow**	N/A
Max	213.226E-09	**NWithinSpec**	N/A
Mean	212.002E-09	**NOutsideSpec**	N/A
StdDev	917.981E-12	**90%**	212.881E-09
25%	211.500E-09	**Range**	3.453E-09
Mean+3*StdDev	214.756E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	209.248E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.6843		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

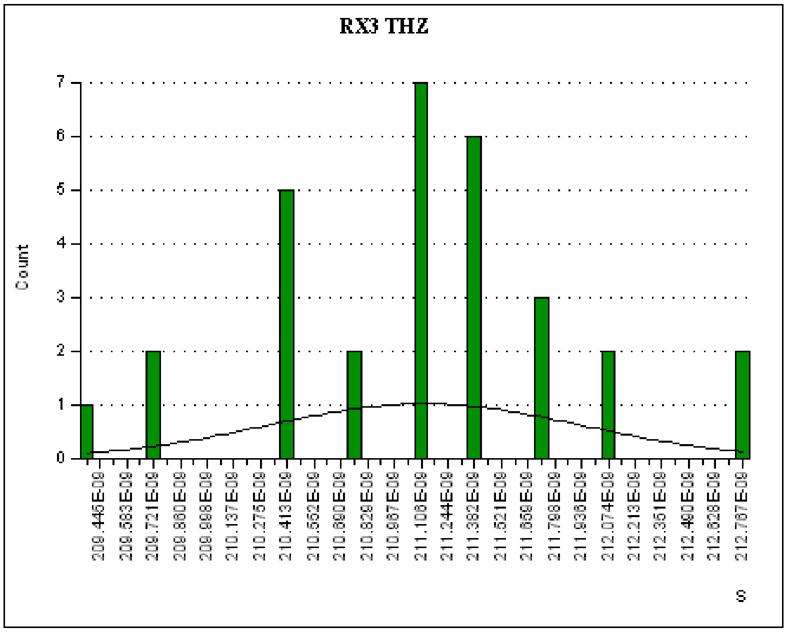
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.012, Test.Name=RX3 THZ



Statistics: (S)

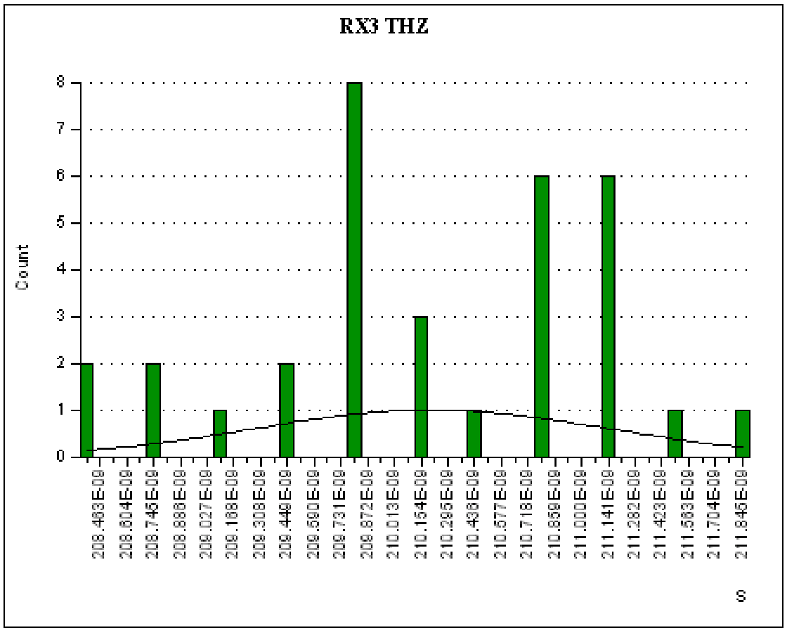
Min	209.375E-09	**Skew**	-0.0285
Max	212.767E-09	**StatHigh**	N/A
Mean	211.105E-09	**StatLow**	N/A
StdDev	808.153E-12	**NWithinSpec**	N/A
25%	210.393E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	213.529E-09	**90%**	212.088E-09
		Range	3.391E-09
Mean-3*StdDev	208.680E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.012, Test.Name=RX3 THZ



Statistics: (S)

Min	208.392E-09	**StatLow**	N/A
Max	211.845E-09	**NWithinSpec**	N/A
Mean	210.192E-09	**NOutsideSpec**	N/A
StdDev	916.627E-12	**90%**	211.155E-09
25%	209.774E-09	**Range**	3.453E-09
Mean+3*StdDev	212.942E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	207.442E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.3073		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

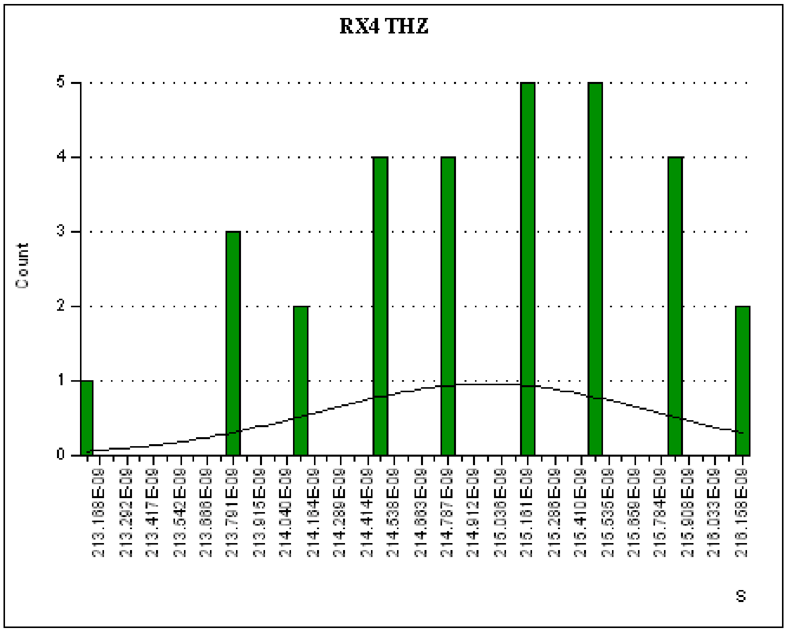
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.013, Test.Name=RX4 THZ



Statistics: (S)

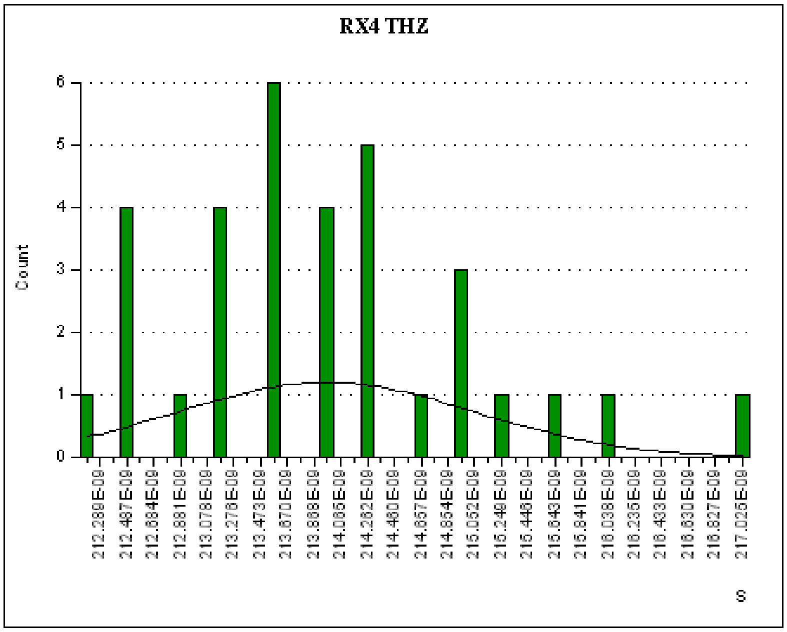
Min	213.106E-09	**Skew**	-0.4468
Max	216.158E-09	**StatHigh**	N/A
Mean	214.948E-09	**StatLow**	N/A
StdDev	774.758E-12	**NWithinSpec**	N/A
25%	214.462E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	217.272E-09	**90%**	215.819E-09
		Range	3.052E-09
Mean-3*StdDev	212.624E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.013, Test.Name=RX4 THZ



Statistics: (S)

Min	212.191E-09	**StatLow**	N/A
Max	217.025E-09	**NWithinSpec**	N/A
Mean	213.938E-09	**NOutsideSpec**	N/A
StdDev	1.081E-09	**90%**	215.298E-09
25%	213.226E-09	**Range**	4.834E-09
Mean+3*StdDev	217.182E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	210.694E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.7850		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

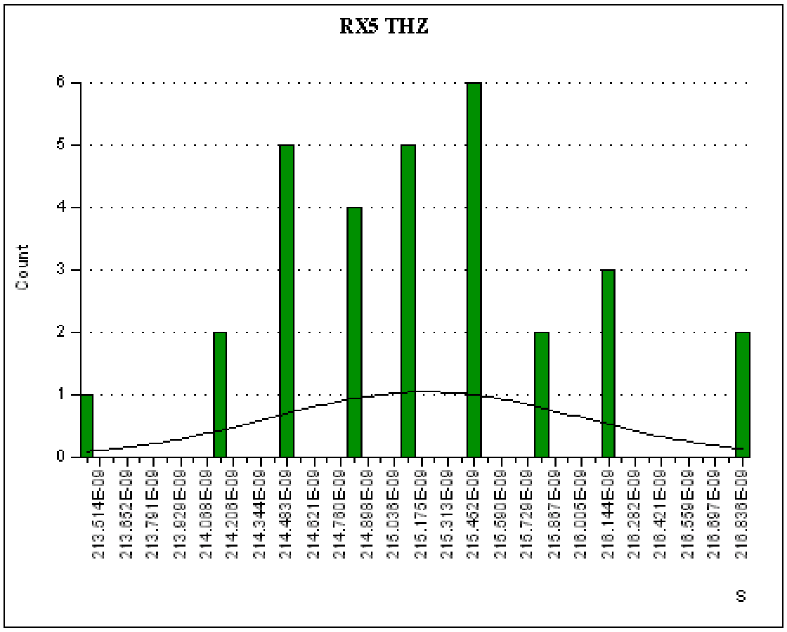
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.014, Test.Name=RX5 THZ



Statistics: (S)

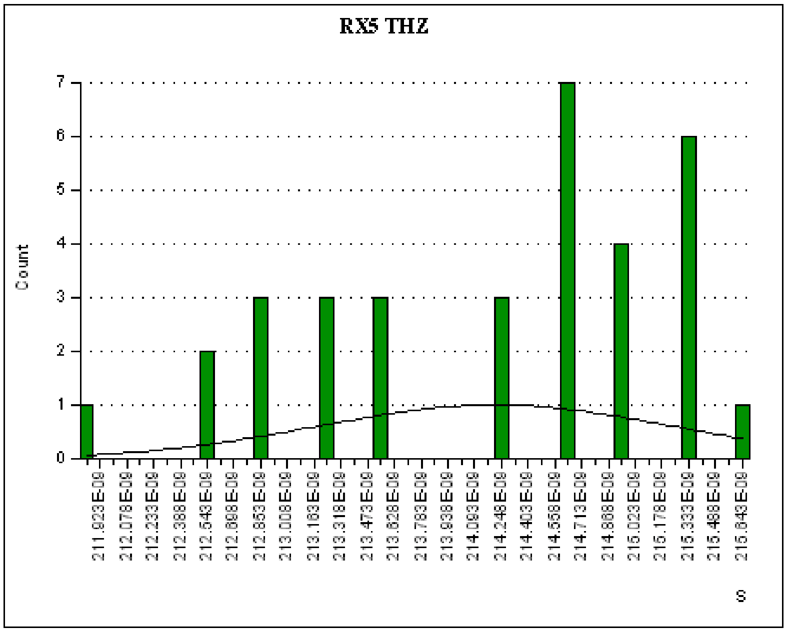
Min	213.445E-09	**Skew**	0.1955
Max	216.836E-09	**StatHigh**	N/A
Mean	215.186E-09	**StatLow**	N/A
StdDev	790.215E-12	**NWithinSpec**	N/A
25%	214.462E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	217.556E-09	**90%**	216.158E-09
		Range	3.391E-09
Mean-3*StdDev	212.815E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.014, Test.Name=RX5 THZ



Statistics: (S)

Min	211.845E-09	**StatLow**	N/A
Max	215.643E-09	**NWithinSpec**	N/A
Mean	214.189E-09	**NOutsideSpec**	N/A
StdDev	1.017E-09	**90%**	215.298E-09
25%	213.226E-09	**Range**	3.798E-09
Mean+3*StdDev	217.240E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	211.139E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.5837		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

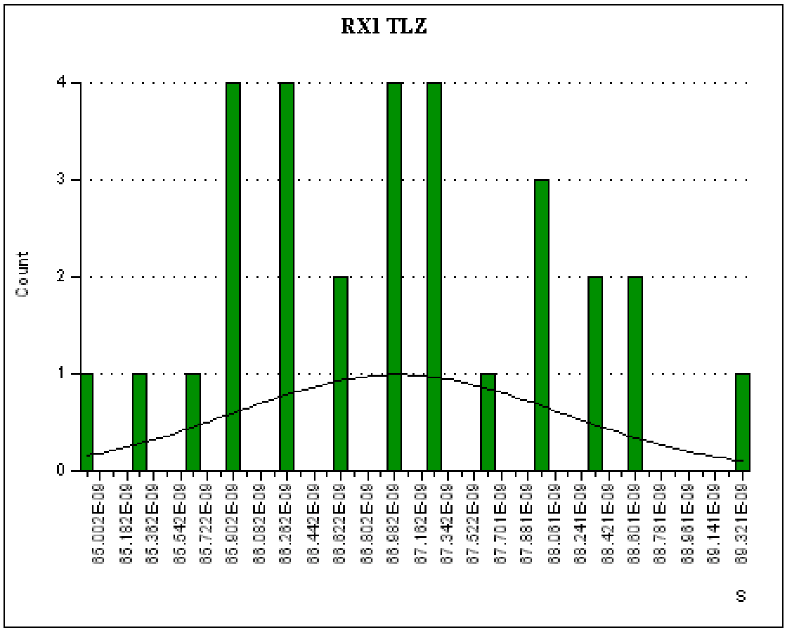
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.015, Test.Name=RX1 TLZ



Statistics: (S)

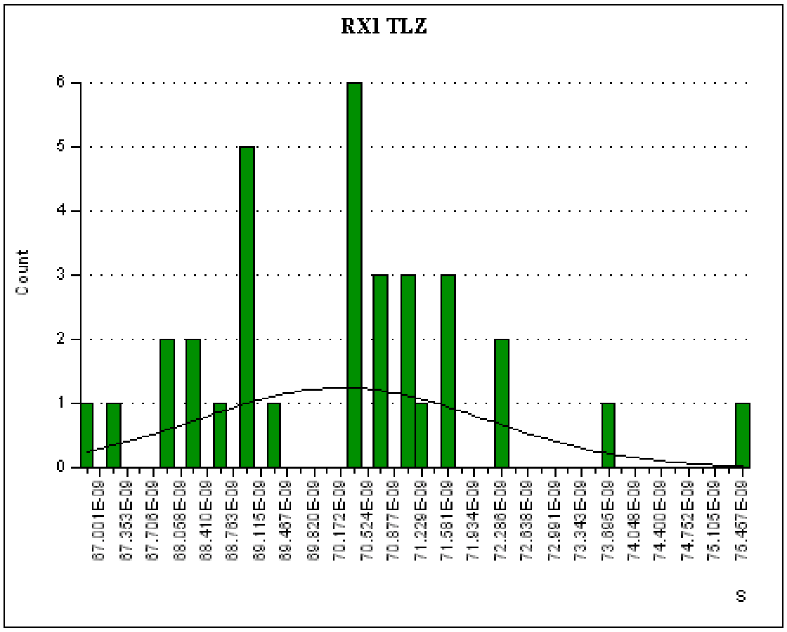
Min	64.912E-09	**Skew**	0.2009
Max	69.321E-09	**StatHigh**	N/A
Mean	66.981E-09	**StatLow**	N/A
StdDev	1.085E-09	**NWithinSpec**	N/A
25%	66.269E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	70.235E-09	**90%**	68.473E-09
		Range	4.408E-09
Mean-3*StdDev	63.727E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.015, Test.Name=RX1 TLZ



Statistics: (S)

Min	66.825E-09	**StatLow**	N/A
Max	75.457E-09	**NWithinSpec**	N/A
Mean	70.152E-09	**NOutsideSpec**	N/A
StdDev	1.861E-09	**90%**	72.349E-09
25%	68.896E-09	**Range**	8.632E-09
Mean+3*StdDev	75.735E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	64.569E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.5842		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

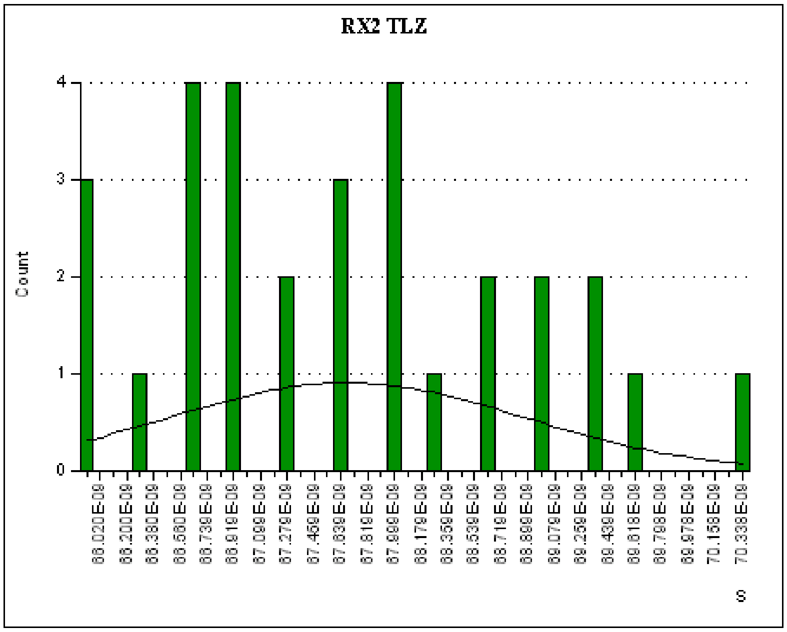
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.016, Test.Name=RX2 TLZ



Statistics: (S)

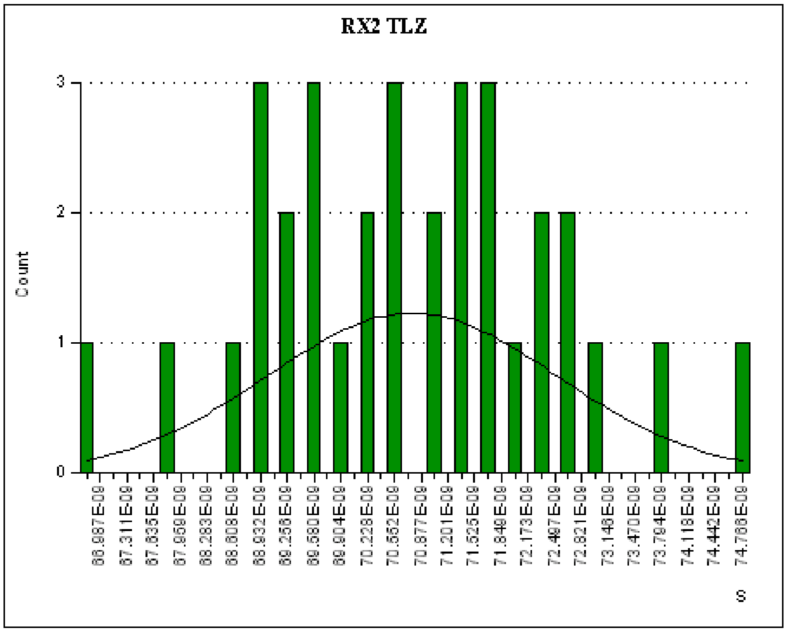
Min	65.930E-09	**Skew**	0.4226
Max	70.338E-09	**StatHigh**	N/A
Mean	67.659E-09	**StatLow**	N/A
StdDev	1.183E-09	**NWithinSpec**	N/A
25%	66.608E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	71.207E-09	**90%**	69.321E-09
		Range	4.408E-09
Mean-3*StdDev	64.111E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.016, Test.Name=RX2 TLZ



Statistics: (S)

Min	66.825E-09	**StatLow**	N/A
Max	74.766E-09	**NWithinSpec**	N/A
Mean	70.728E-09	**NOutsideSpec**	N/A
StdDev	1.738E-09	**90%**	72.695E-09
25%	69.587E-09	**Range**	7.942E-09
Mean+3*StdDev	75.942E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	65.513E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0683		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

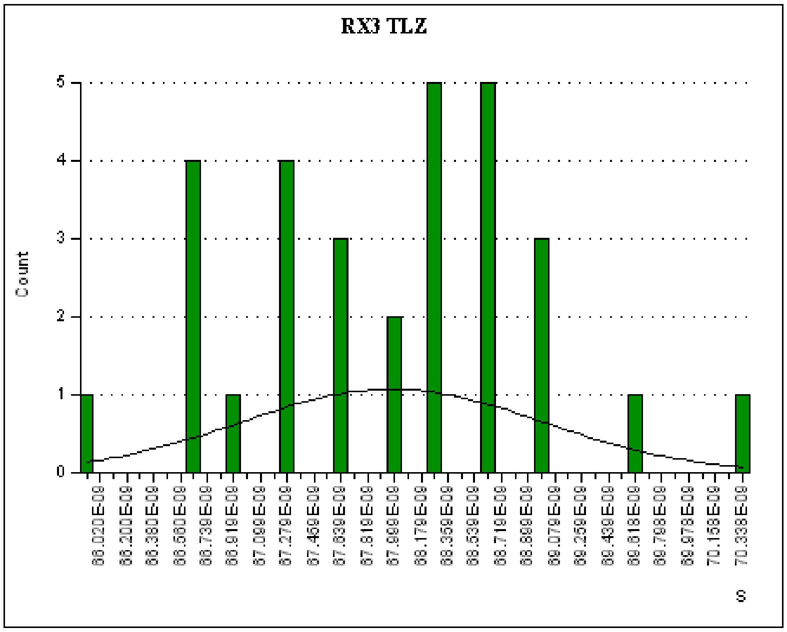
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.017, Test.Name=RX3 TLZ



Statistics: (S)

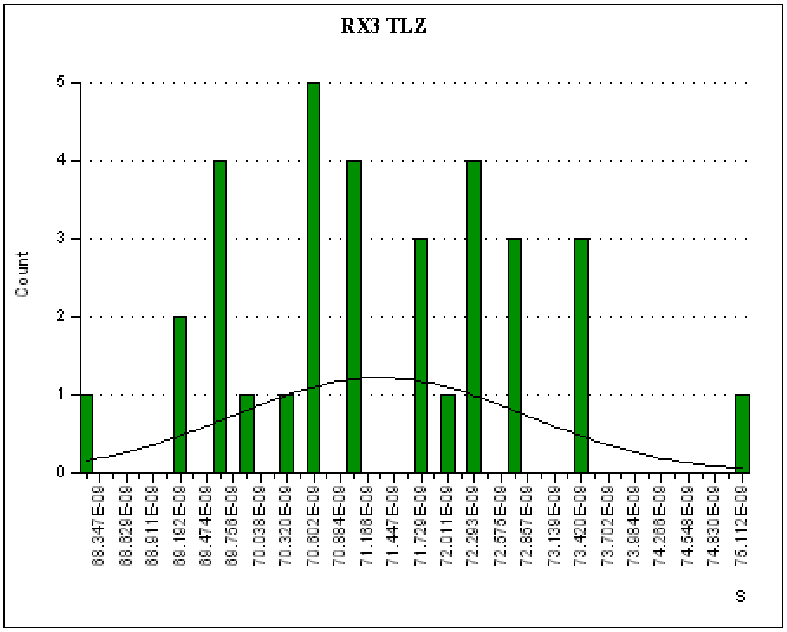
Min	65.930E-09	**Skew**	0.0855
Max	70.338E-09	**StatHigh**	N/A
Mean	67.964E-09	**StatLow**	N/A
StdDev	1.004E-09	**NWithinSpec**	N/A
25%	67.286E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	70.975E-09	**90%**	68.982E-09
		Range	4.408E-09
Mean-3*StdDev	64.954E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.017, Test.Name=RX3 TLZ



Statistics: (S)

Min	68.206E-09	**StatLow**	N/A
Max	75.112E-09	**NWithinSpec**	N/A
Mean	71.272E-09	**NOutsideSpec**	N/A
StdDev	1.522E-09	**90%**	73.385E-09
25%	70.278E-09	**Range**	6.906E-09
Mean+3*StdDev	75.837E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	66.707E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2798		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

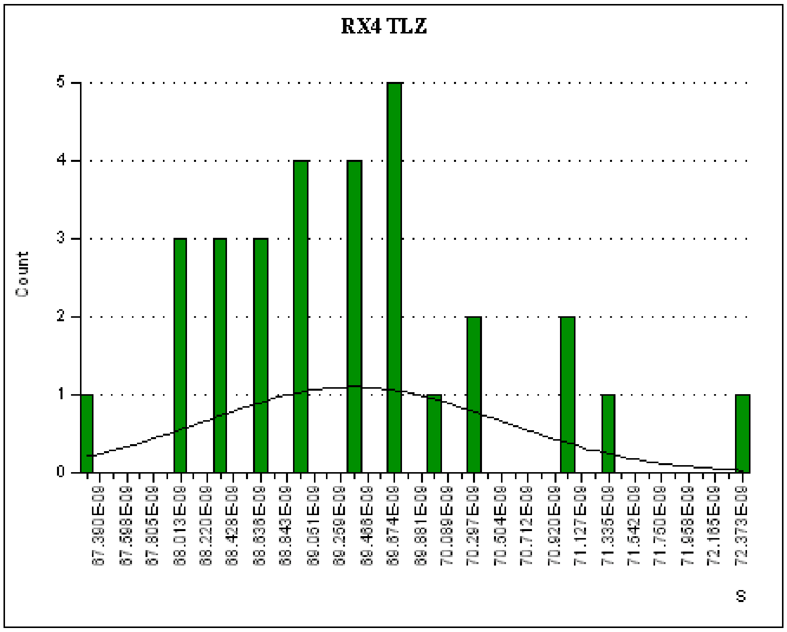
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.018, Test.Name=RX4 TLZ



Statistics: (S)

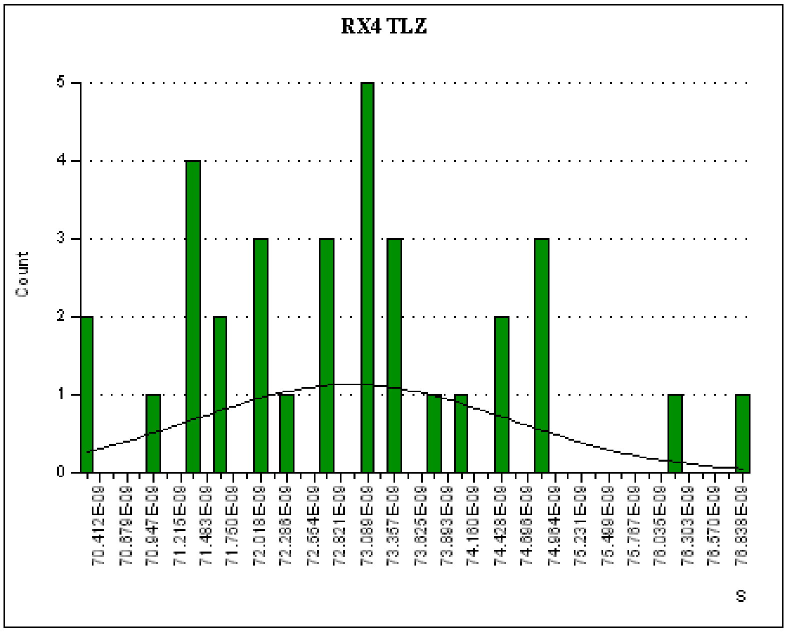
Min	67.286E-09	**Skew**	0.7153
Max	72.373E-09	**StatHigh**	N/A
Mean	69.332E-09	**StatLow**	N/A
StdDev	1.128E-09	**NWithinSpec**	N/A
25%	68.643E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	72.717E-09	**90%**	71.016E-09
		Range	5.087E-09
Mean-3*StdDev	65.948E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.018, Test.Name=RX4 TLZ



Statistics: (S)

Min	70.278E-09	**StatLow**	N/A
Max	76.838E-09	**NWithinSpec**	N/A
Mean	72.904E-09	**NOutsideSpec**	N/A
StdDev	1.556E-09	**90%**	74.766E-09
25%	71.659E-09	**Range**	6.560E-09
Mean+3*StdDev	77.572E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	68.236E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.5129		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

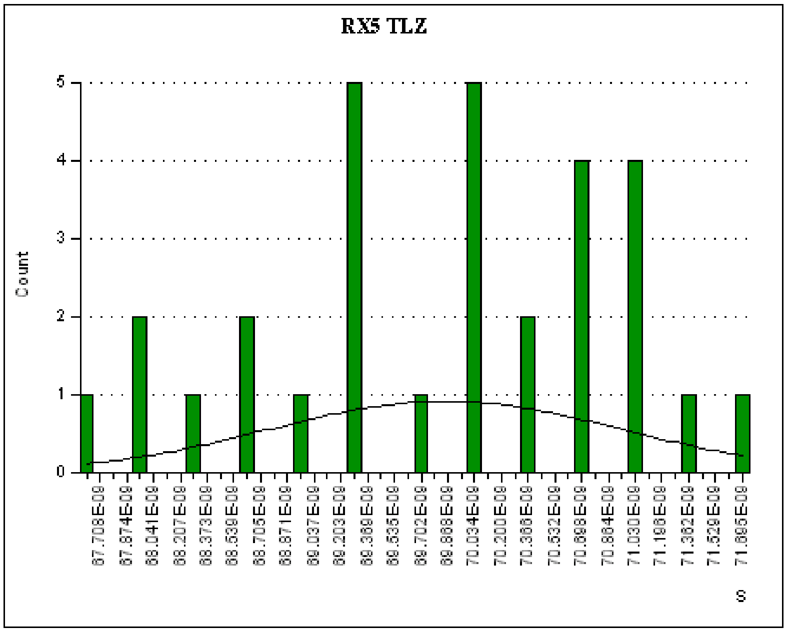
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=19.019, Test.Name=RX5 TLZ



Statistics: (S)

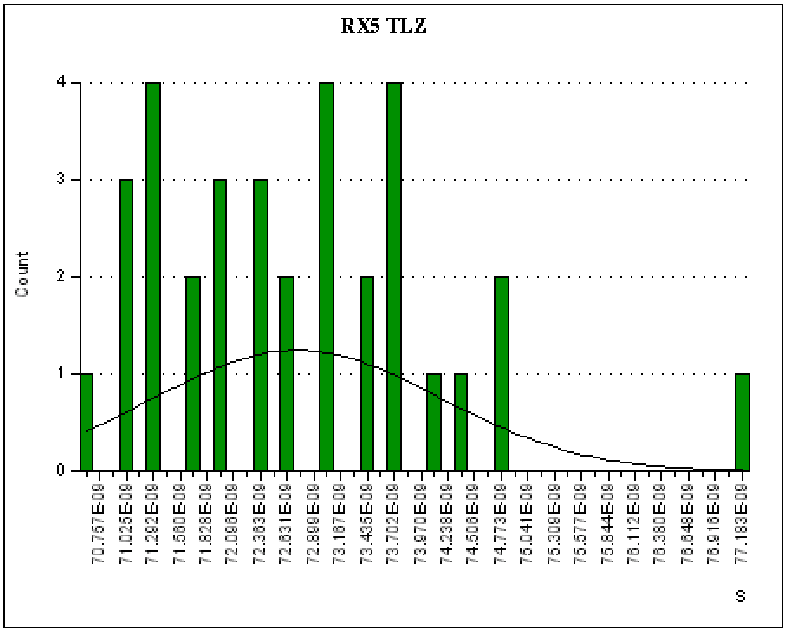
Min	67.625E-09	**Skew**	-0.3612
Max	71.695E-09	**StatHigh**	N/A
Mean	69.830E-09	**StatLow**	N/A
StdDev	1.082E-09	**NWithinSpec**	N/A
25%	69.321E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	73.077E-09	**90%**	71.016E-09
		Range	4.069E-09
Mean-3*StdDev	66.582E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.019, Test.Name=RX5 TLZ



Statistics: (S)

Min	70.623E-09	**StatLow**	N/A
Max	77.183E-09	**NWithinSpec**	N/A
Mean	72.716E-09	**NOutsideSpec**	N/A
StdDev	1.416E-09	**90%**	74.421E-09
25%	71.659E-09	**Range**	6.560E-09
Mean+3*StdDev	76.962E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	68.469E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.9269		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

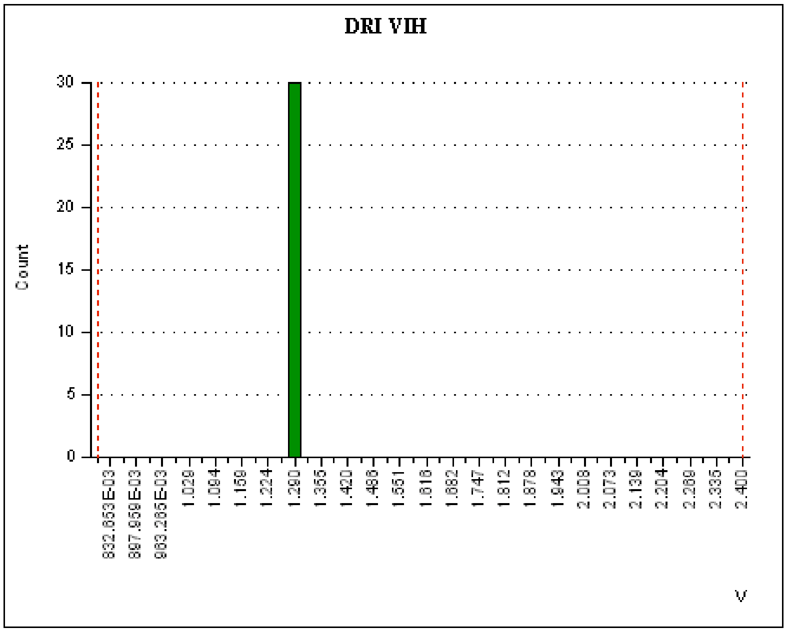
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=20.000, Test.Name=DRI VIH



Statistics: (V)

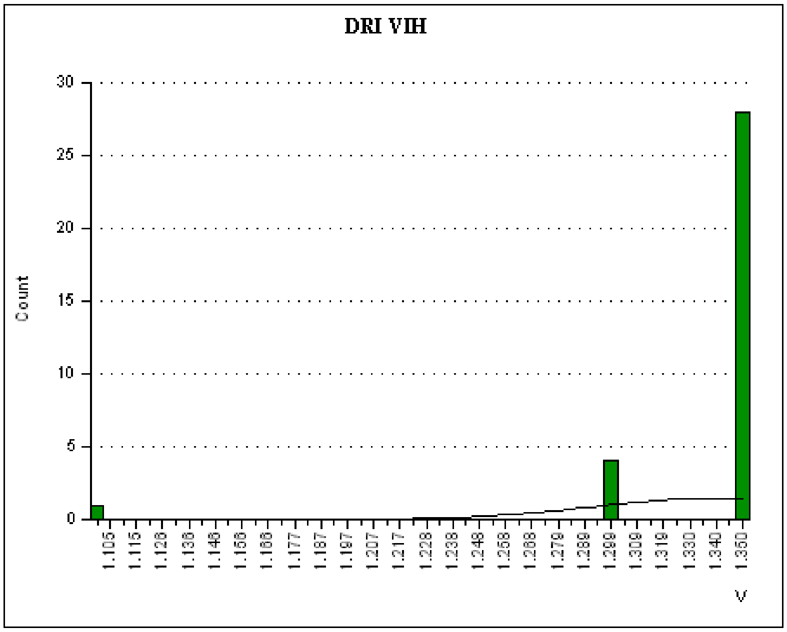
Min	1.300	**Skew**	N/A
Max	1.300	**StatHigh**	N/A
Mean	1.300	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.300	**90%**	1.300
		Range	0
Mean-3*StdDev	1.300	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.000, Test.Name=DRI VIH



Statistics: (V)

Min	1.100	**StatLow**	N/A
Max	1.350	**NWithinSpec**	N/A
Mean	1.336	**NOutsideSpec**	N/A
StdDev	45.540E-03	**90%**	1.350
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.473	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.200	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-4.6940		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

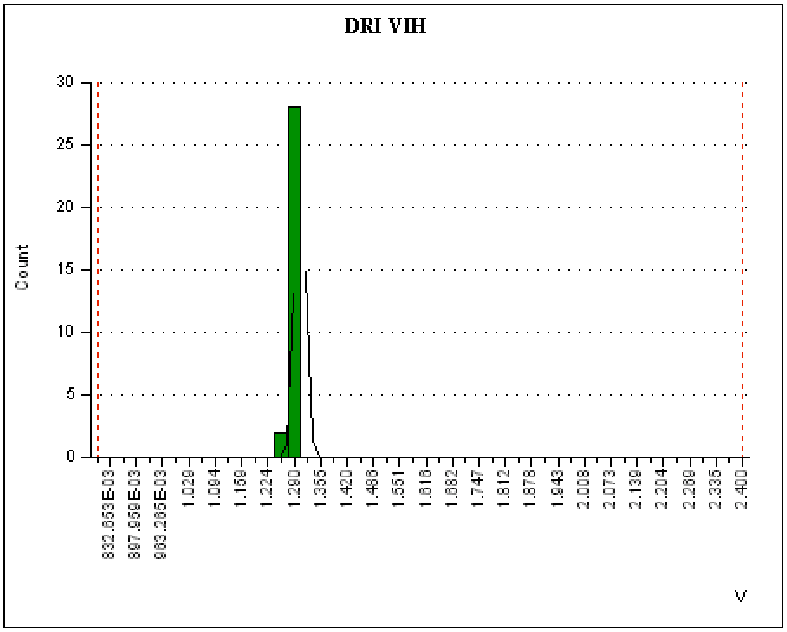
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=20.002, Test.Name=DRI VIH



Statistics: (V)

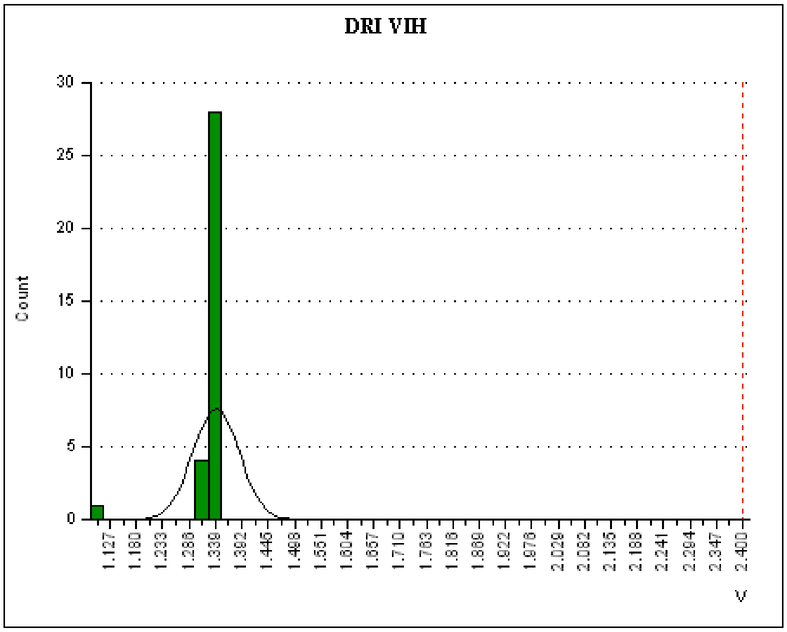
Min	1.250	**Skew**	-3.6600
Max	1.300	**StatHigh**	N/A
Mean	1.297	**StatLow**	N/A
StdDev	12.685E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.335	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.259	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.002, Test.Name=DRI VIH



Statistics: (V)

Min	1.100	**StatLow**	N/A
Max	1.350	**NWithinSpec**	33
Mean	1.336	**NOutsideSpec**	0
StdDev	45.540E-03	**90%**	1.350
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.473	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.200	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-4.6940		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

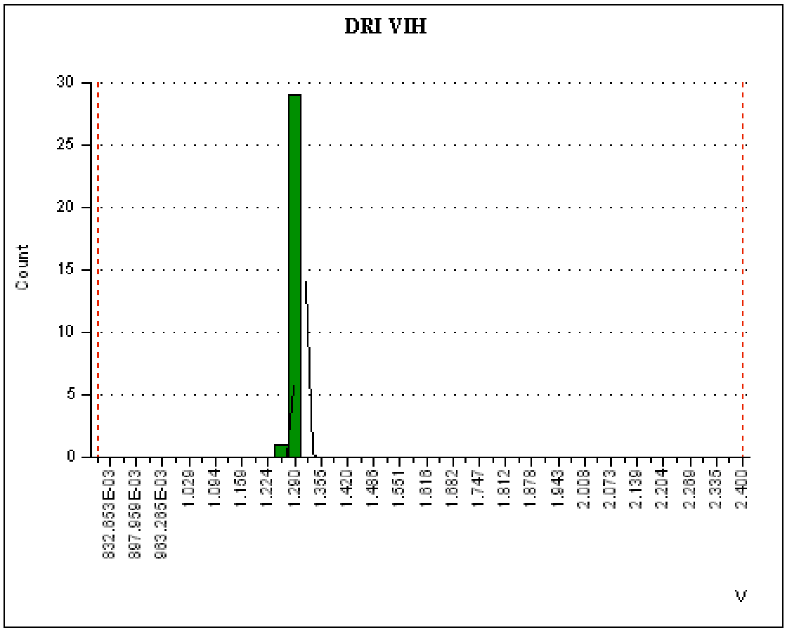
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=20.004, Test.Name=DRI VIH



Statistics: (V)

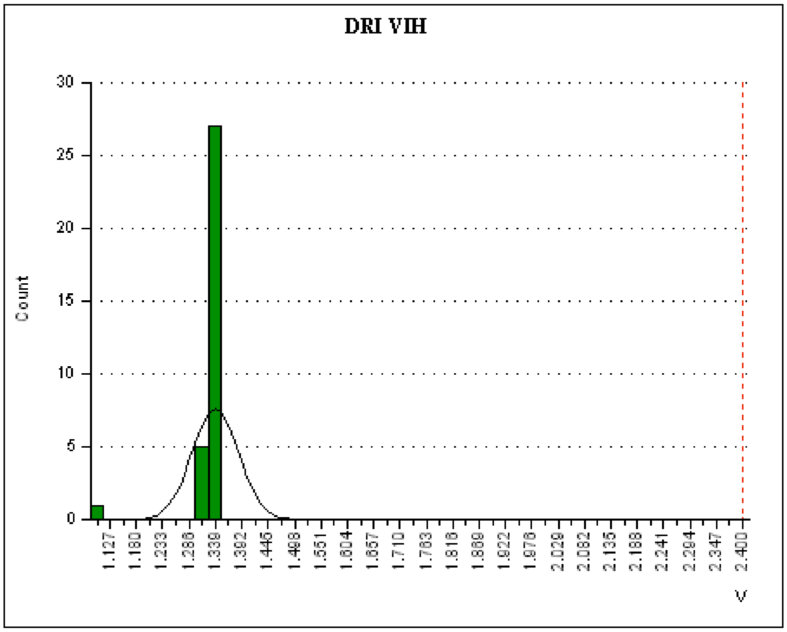
Min	1.250	**Skew**	-5.4772
Max	1.300	**StatHigh**	N/A
Mean	1.298	**StatLow**	N/A
StdDev	9.129E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.326	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.271	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.004, Test.Name=DRI VIH



Statistics: (V)

Min	1.100	**StatLow**	N/A
Max	1.350	**NWithinSpec**	33
Mean	1.335	**NOutsideSpec**	0
StdDev	45.902E-03	**90%**	1.350
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.473	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.197	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-4.4957		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

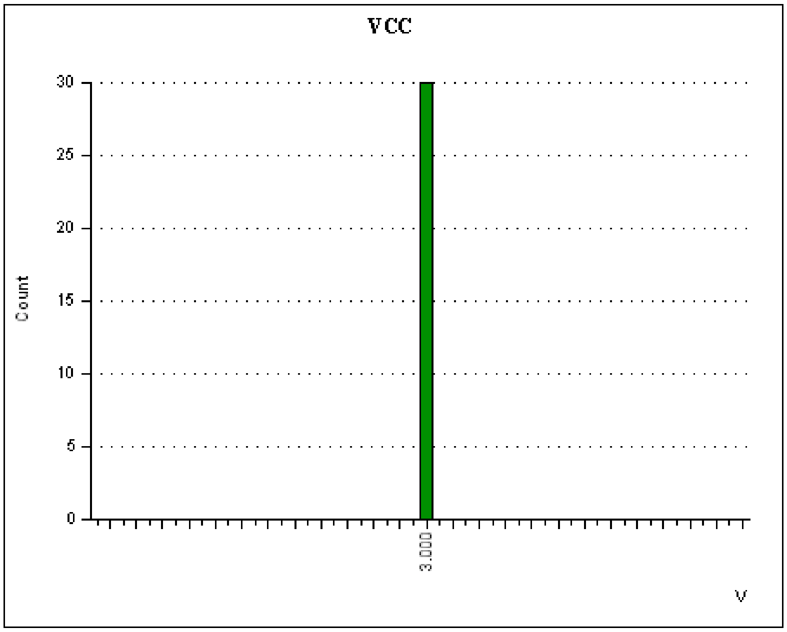
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=21.000, Test.Name=VCC



Statistics: (V)

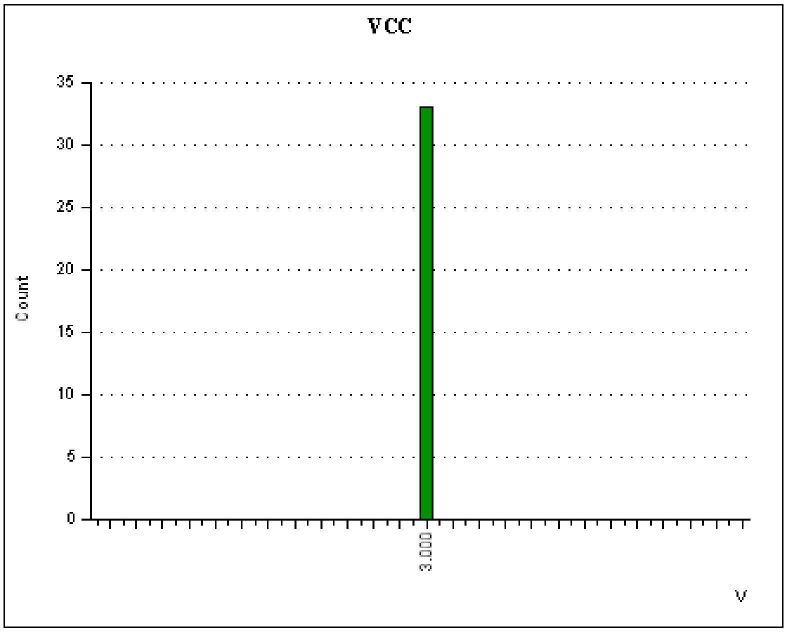
Min	3.000	**Skew**	N/A
Max	3.000	**StatHigh**	N/A
Mean	3.000	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	3.000	**NOutsideSpec**	N/A
Mean+3*StdDev	3.000	**90%**	3.000
		Range	0
Mean-3*StdDev	3.000	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=21.000, Test.Name=VCC



Statistics: (V)

Min	3.000	**StatLow**	N/A
Max	3.000	**NWithinSpec**	N/A
Mean	3.000	**NOutsideSpec**	N/A
StdDev	0	**90%**	3.000
25%	3.000	**Range**	0
Mean+3*StdDev	3.000	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	3.000	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	N/A		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

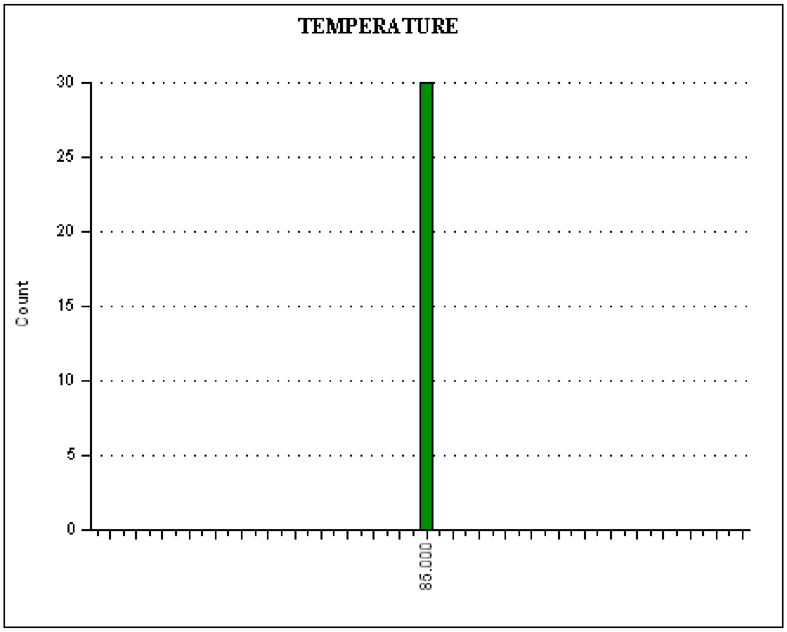
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=21.001, Test.Name=TEMPERATURE



Statistics

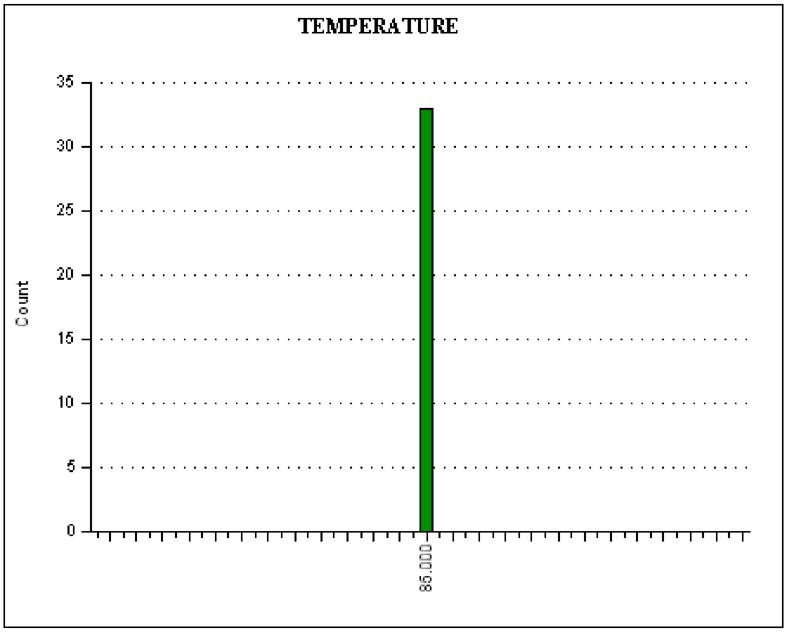
Min	85.000	**Skew**	N/A
Max	85.000	**StatHigh**	N/A
Mean	85.000	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	85.000	**NOutsideSpec**	N/A
Mean+3*StdDev	85.000	**90%**	85.000
		Range	0
Mean-3*StdDev	85.000	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=21.001, Test.Name=TEMPERATURE



Statistics

Min	85.000	**StatLow**	N/A
Max	85.000	**NWithinSpec**	N/A
Mean	85.000	**NOutsideSpec**	N/A
StdDev	0	**90%**	85.000
25%	85.000	**Range**	0
Mean+3*StdDev	85.000	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	85.000	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	N/A		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

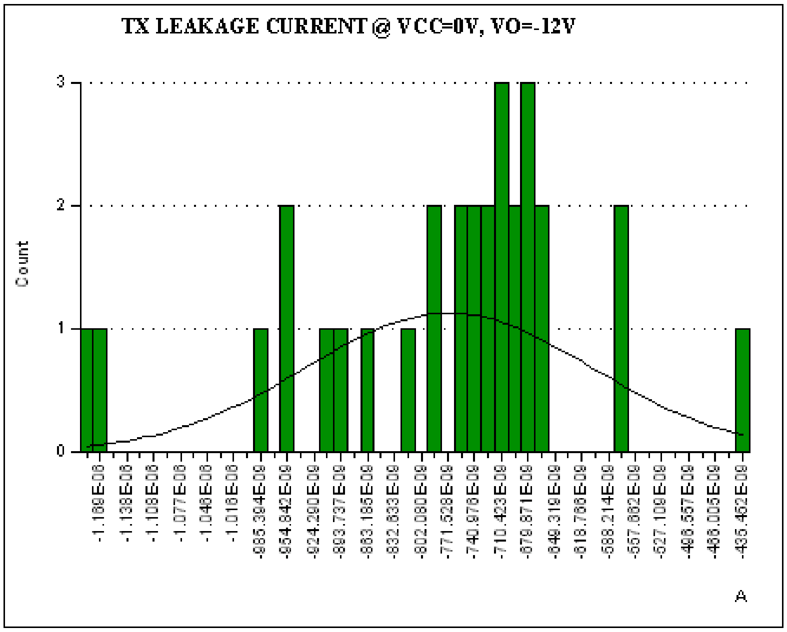
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=22.000, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

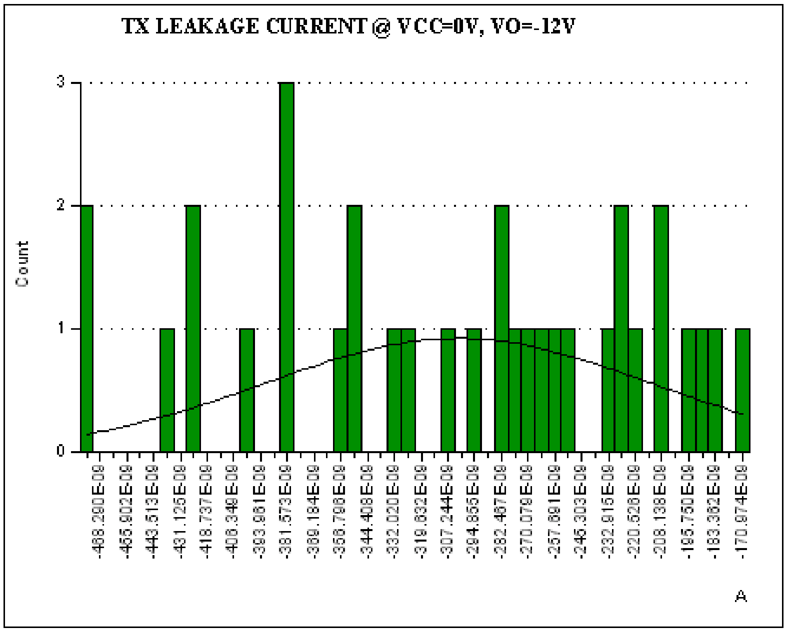
Min	-1.184E-06	**Skew**	-0.8342
Max	-435.452E-09	**StatHigh**	N/A
Mean	-774.667E-09	**StatLow**	N/A
StdDev	161.876E-09	**NWithinSpec**	N/A
25%	-868.928E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	-289.040E-09	**90%**	-618.314E-09
		Range	748.532E-09
Mean-3*StdDev	-1.260E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.000, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-474.484E-09	**StatLow**	N/A
Max	-170.974E-09	**NWithinSpec**	N/A
Mean	-304.192E-09	**NOutsideSpec**	N/A
StdDev	88.336E-09	**90%**	-192.941E-09
25%	-380.730E-09	**Range**	303.510E-09
Mean+3*StdDev	-39.184E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-569.200E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.3463		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

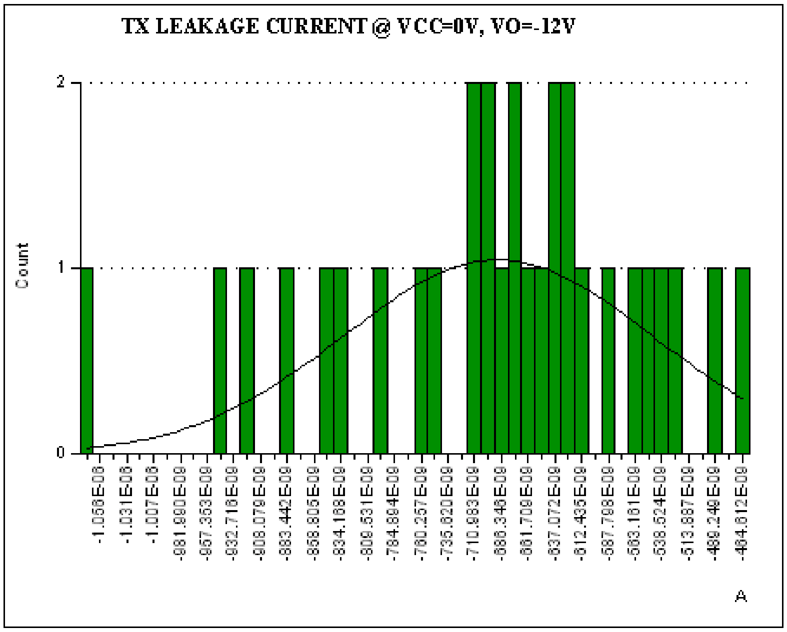
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=22.001, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

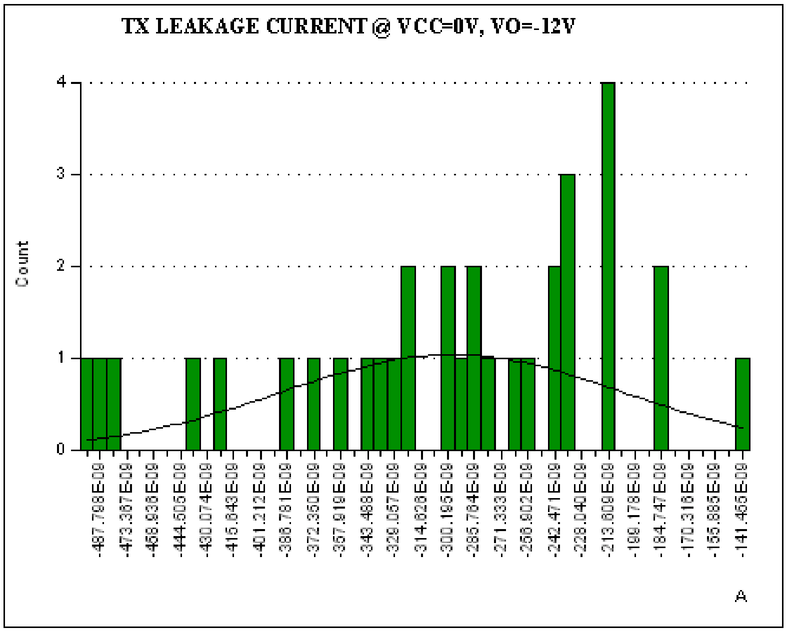
Min	-1.068E-06	**Skew**	-0.7392
Max	-464.612E-09	**StatHigh**	N/A
Mean	-693.505E-09	**StatLow**	N/A
StdDev	141.040E-09	**NWithinSpec**	N/A
25%	-761.554E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	-270.384E-09	**90%**	-532.880E-09
		Range	603.607E-09
Mean-3*StdDev	-1.117E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.001, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-495.014E-09	**StatLow**	N/A
Max	-141.455E-09	**NWithinSpec**	N/A
Mean	-299.974E-09	**NOutsideSpec**	N/A
StdDev	91.189E-09	**90%**	-210.231E-09
25%	-340.154E-09	**Range**	353.559E-09
Mean+3*StdDev	-26.406E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-573.542E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.6470		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

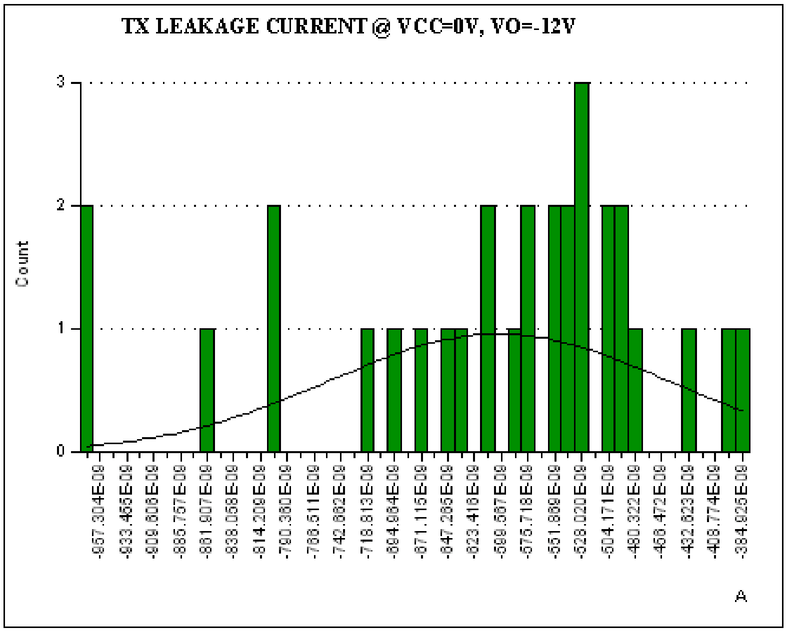
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=22.002, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

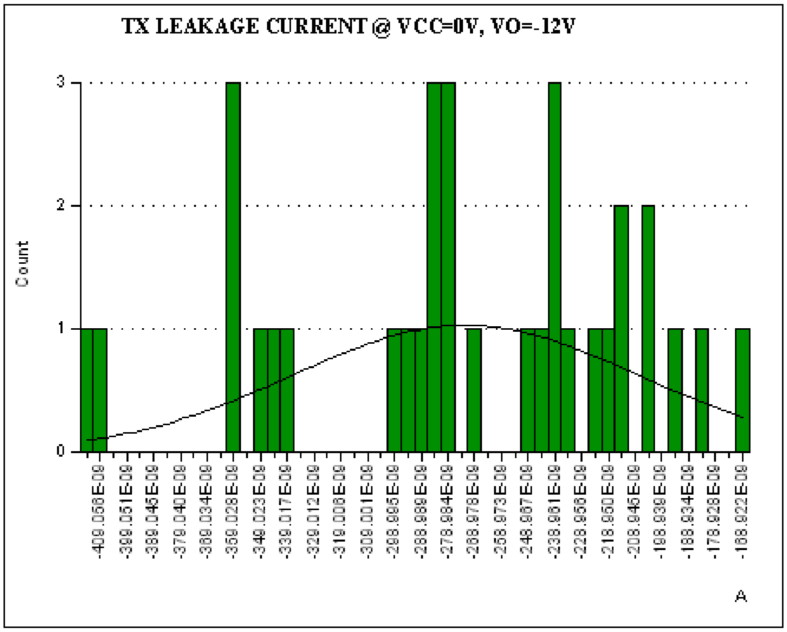
Min	-969.228E-09	**Skew**	-1.0728
Max	-384.925E-09	**StatHigh**	N/A
Mean	-605.495E-09	**StatLow**	N/A
StdDev	148.690E-09	**NWithinSpec**	N/A
25%	-666.410E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	-159.425E-09	**90%**	-459.750E-09
		Range	584.303E-09
Mean-3*StdDev	-1.052E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.002, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-414.059E-09	**StatLow**	N/A
Max	-168.922E-09	**NWithinSpec**	N/A
Mean	-273.847E-09	**NOutsideSpec**	N/A
StdDev	63.936E-09	**90%**	-201.586E-09
25%	-297.166E-09	**Range**	245.137E-09
Mean+3*StdDev	-82.040E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-465.654E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.5063		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

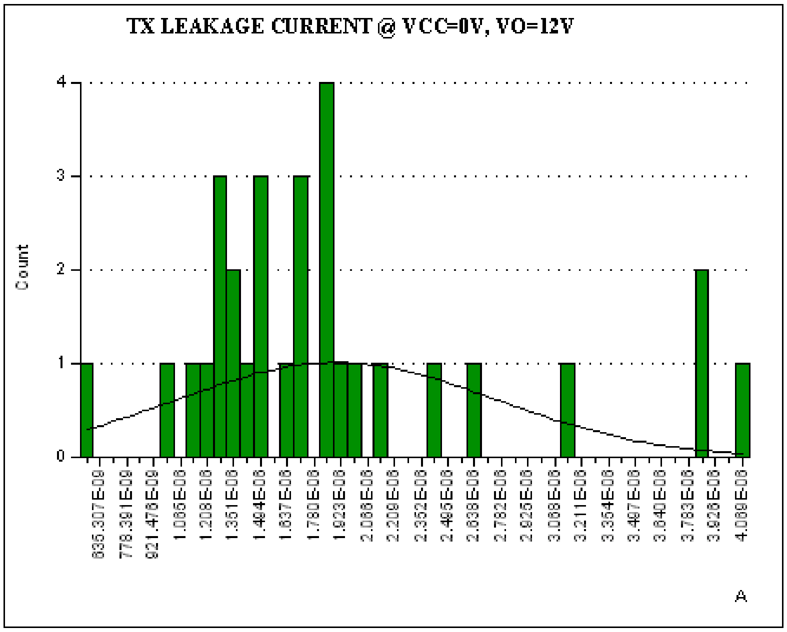
Conditions

Temp	**Vcc**
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=22.003, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

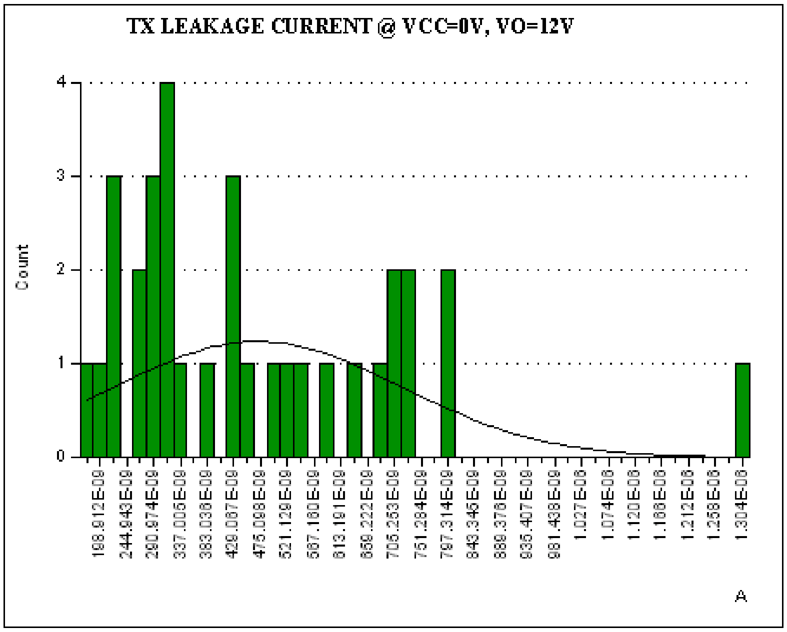
Min	563.764E-09	**Skew**	1.3791
Max	4.069E-06	**StatHigh**	N/A
Mean	1.887E-06	**StatLow**	N/A
StdDev	846.282E-09	**NWithinSpec**	N/A
25%	1.341E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	4.425E-06	**90%**	3.474E-06
		Range	3.506E-06
Mean-3*StdDev	-652.234E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.003, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	175.896E-09	**StatLow**	N/A
Max	1.304E-06	**NWithinSpec**	N/A
Mean	467.441E-09	**NOutsideSpec**	N/A
StdDev	245.081E-09	**90%**	730.325E-09
25%	292.350E-09	**Range**	1.128E-06
Mean+3*StdDev	1.203E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-267.802E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.3658		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

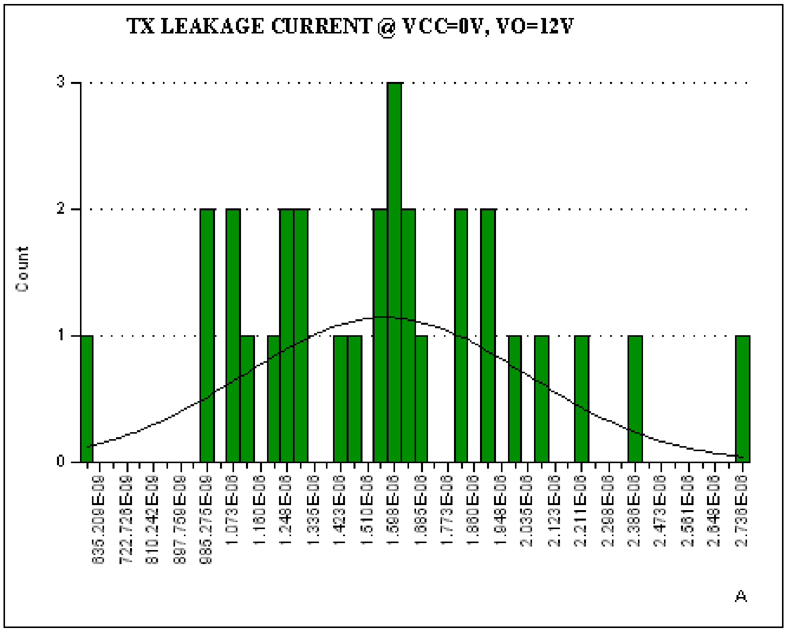
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=22.004, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

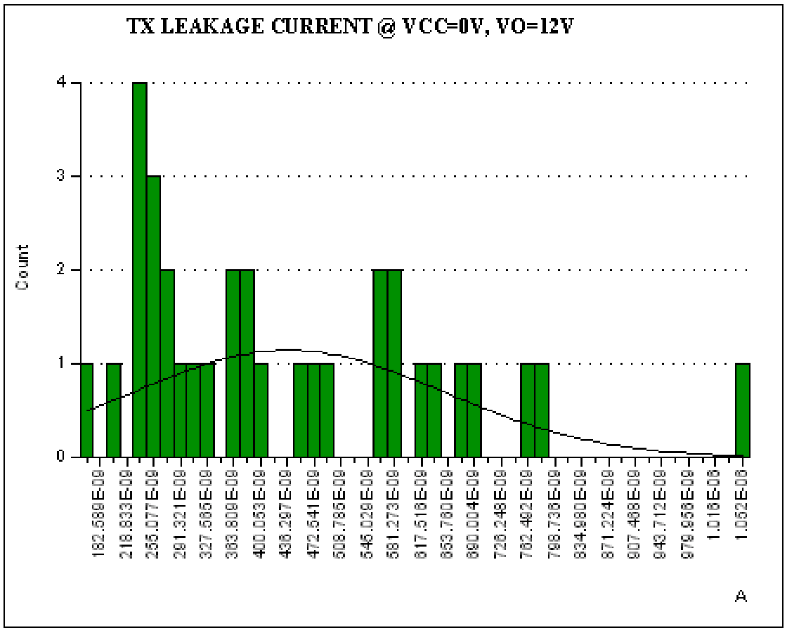
Min	591.451E-09	**Skew**	0.4108
Max	2.736E-06	**StatHigh**	N/A
Mean	1.558E-06	**StatLow**	N/A
StdDev	457.042E-09	**NWithinSpec**	N/A
25%	1.244E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	2.929E-06	**90%**	2.142E-06
		Range	2.144E-06
Mean-3*StdDev	186.723E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.004, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	164.467E-09	**StatLow**	N/A
Max	1.052E-06	**NWithinSpec**	N/A
Mean	435.781E-09	**NOutsideSpec**	N/A
StdDev	208.567E-09	**90%**	691.800E-09
25%	259.540E-09	**Range**	887.976E-09
Mean+3*StdDev	1.061E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-189.921E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.9884		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

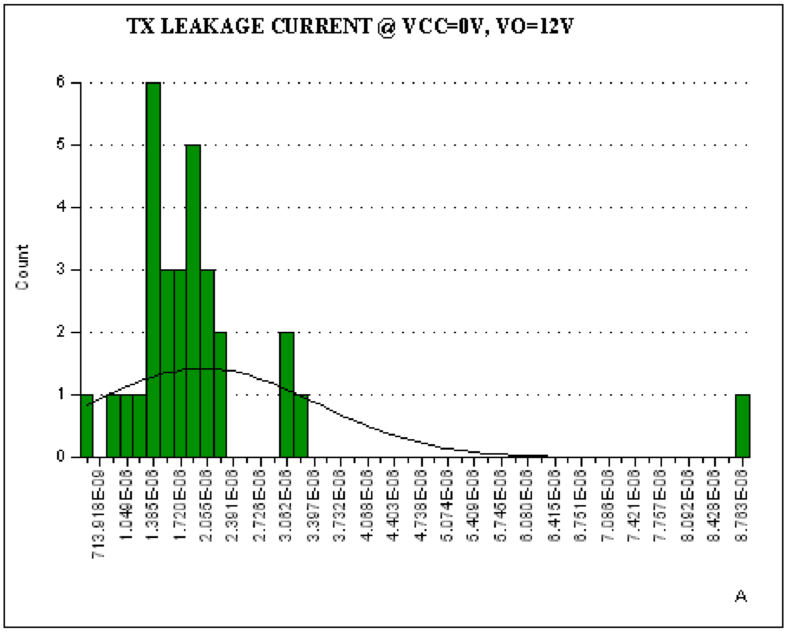
Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Thu 30 Mar 2006, 11:32 AM

Test.Number=22.005, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

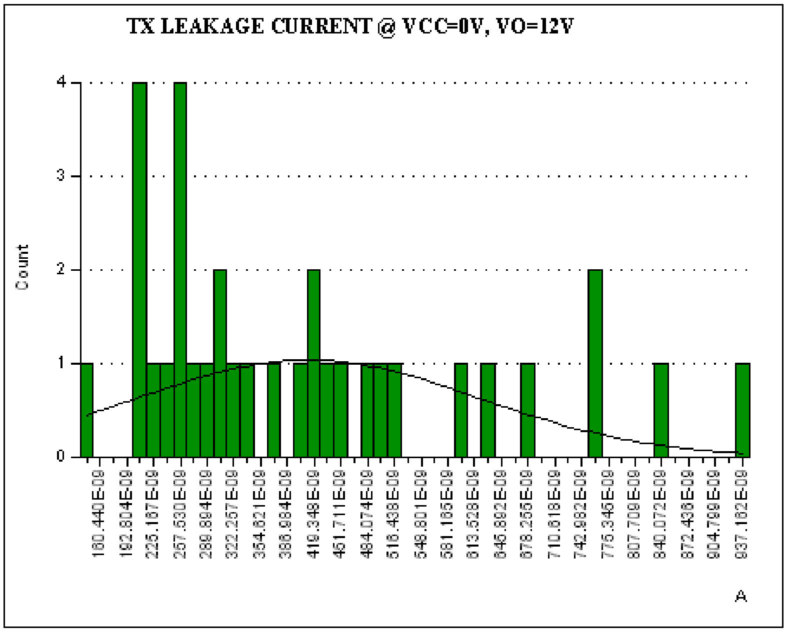
Min	546.229E-09	**Skew**	4.0553
Max	8.763E-06	**StatHigh**	N/A
Mean	1.990E-06	**StatLow**	N/A
StdDev	1.410E-06	**NWithinSpec**	N/A
25%	1.415E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	6.221E-06	**90%**	3.054E-06
		Range	8.217E-06
Mean-3*StdDev	-2.241E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	85oC3Vchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.005, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	144.258E-09	**StatLow**	N/A
Max	937.162E-09	**NWithinSpec**	N/A
Mean	409.395E-09	**NOutsideSpec**	N/A
StdDev	205.281E-09	**90%**	764.094E-09
25%	259.686E-09	**Range**	792.904E-09
Mean+3*StdDev	1.025E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-206.449E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.0369		
StatHigh	N/A		

Attributes

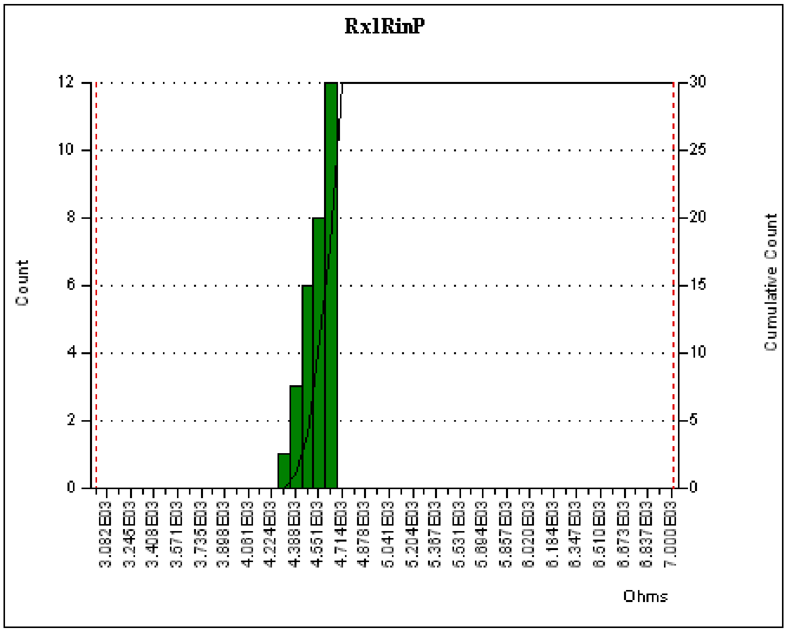
Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	09-JUL-2003	N/A	SP3243ECH.AT	-	0

Conditions

Temp	Vcc
85C	3V

Data: Raw Data

Test.Number=28.0, Test.Name=Rx1RinP



Statistics: (Ohms)

Max	4.669E03	**25%**	4.498E03	**SpecHigh**	7.000E03
Mean	4.539E03	**10%**	4.402E03	**SpecLow**	3.000E03
Min	4.323E03	**N**	30	**PctWithinSpec**	100.00
Range	346.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	86.117	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9285	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.0447	**Cpk**	>4.0000		
90%	4.623E03	**Skew**	-0.8506		
75%	4.606E03	**Kurtosis**	0.0874		
Median	4.561E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

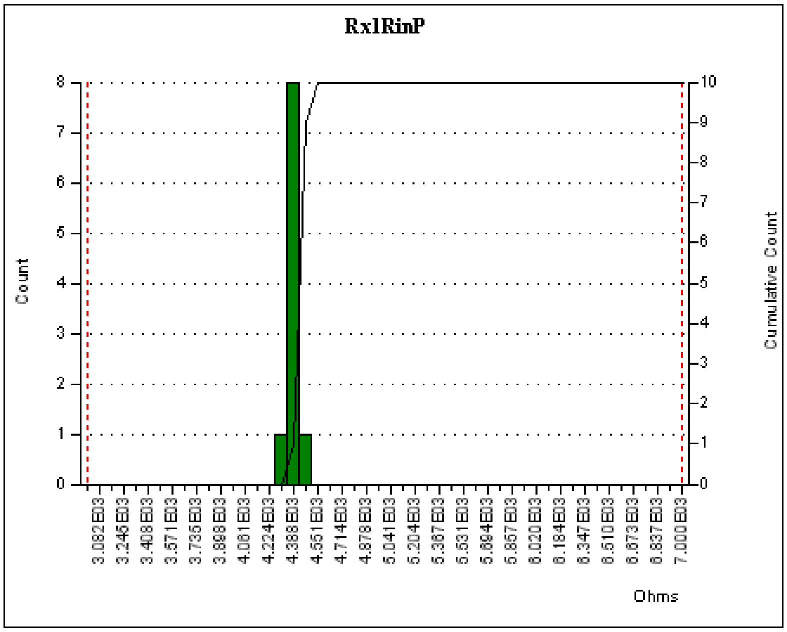
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=28.0, Test.Name=Rx1RinP



Statistics: (Ohms)

Max	4.443E03	**25%**	4.364E03	**SpecHigh**	7.000E03
Mean	4.384E03	**10%**	4.332E03	**SpecLow**	3.000E03
Min	4.318E03	**N**	10	**PctWithinSpec**	100.00
Range	125.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	36.978	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9830	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9791	**Cpk**	>4.0000		
90%	4.429E03	**Skew**	-0.2012		
75%	4.410E03	**Kurtosis**	-0.2715		
Median	4.384E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

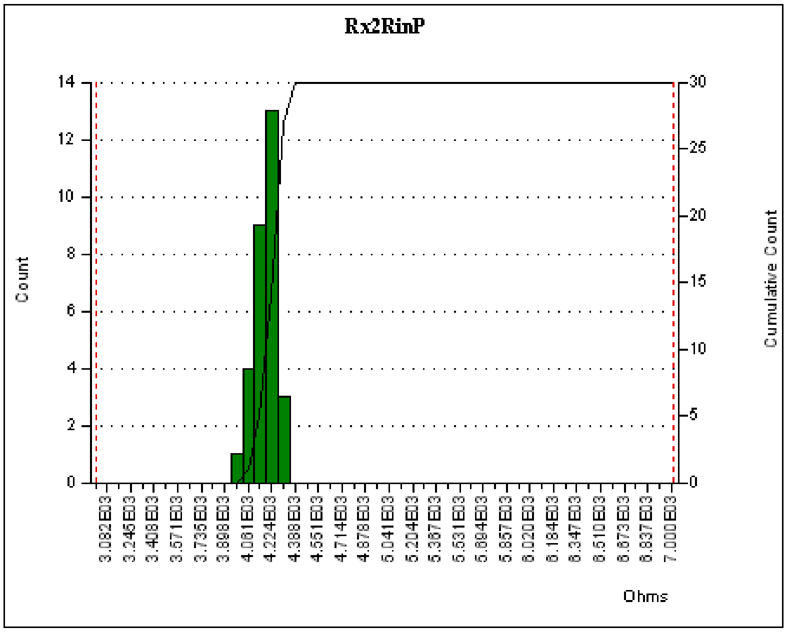
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=29.0, Test.Name=Rx2RinP



Statistics: (Ohms)

Max	4.321E03	**25%**	4.146E03	**SpecHigh**	7.000E03
Mean	4.185E03	**10%**	4.056E03	**SpecLow**	3.000E03
Min	3.976E03	**N**	30	**PctWithinSpec**	100.00
Range	345.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	84.089	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9502	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1717	**Cpk**	>4.0000		
90%	4.272E03	**Skew**	-0.7171		
75%	4.256E03	**Kurtosis**	0.0302		
Median	4.203E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

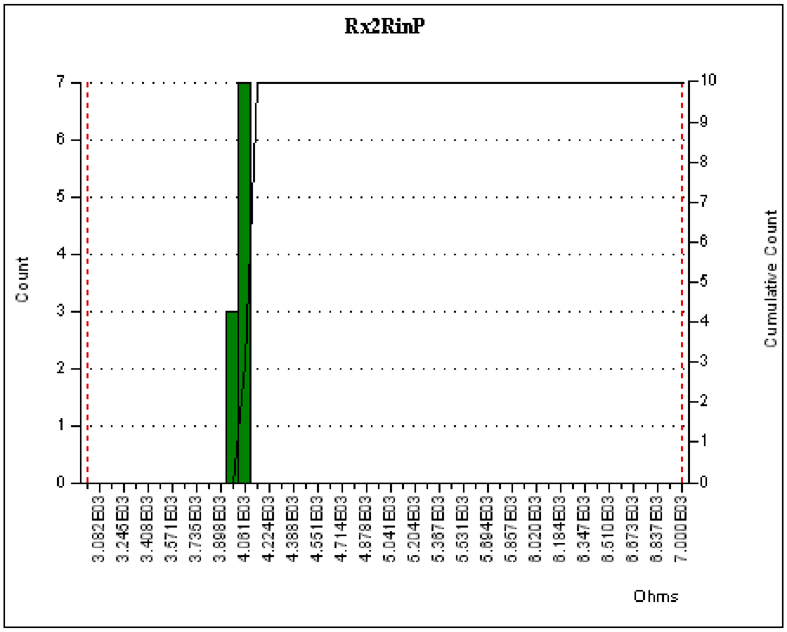
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=29.0, Test.Name=Rx2RinP



Statistics: (Ohms)

Max	4.099E03	**25%**	4.013E03	**SpecHigh**	7.000E03
Mean	4.035E03	**10%**	3.977E03	**SpecLow**	3.000E03
Min	3.959E03	**N**	10	**PctWithinSpec**	100.00
Range	140.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	40.836	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9926	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9990	**Cpk**	>4.0000		
90%	4.088E03	**Skew**	-0.2891		
75%	4.063E03	**Kurtosis**	0.1003		
Median	4.035E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

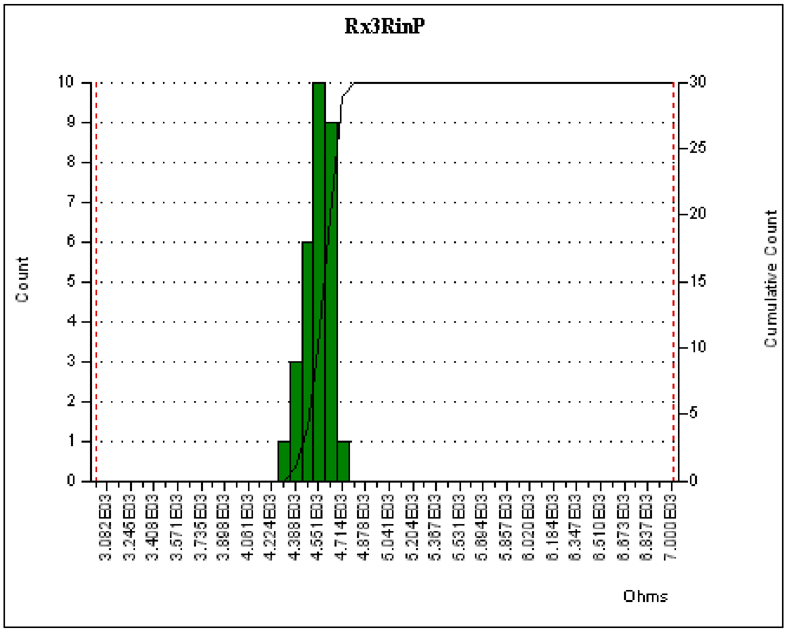
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=30.0, Test.Name=Rx3RinP



Statistics: (Ohms)

Max	4.674E03	**25%**	4.492E03	**SpecHigh**	7.000E03
Mean	4.538E03	**10%**	4.407E03	**SpecLow**	3.000E03
Min	4.328E03	**N**	30	**PctWithinSpec**	100.00
Range	346.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	83.510	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9475	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1446	**Cpk**	>4.0000		
90%	4.622E03	**Skew**	-0.7516		
75%	4.606E03	**Kurtosis**	0.1316		
Median	4.559E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

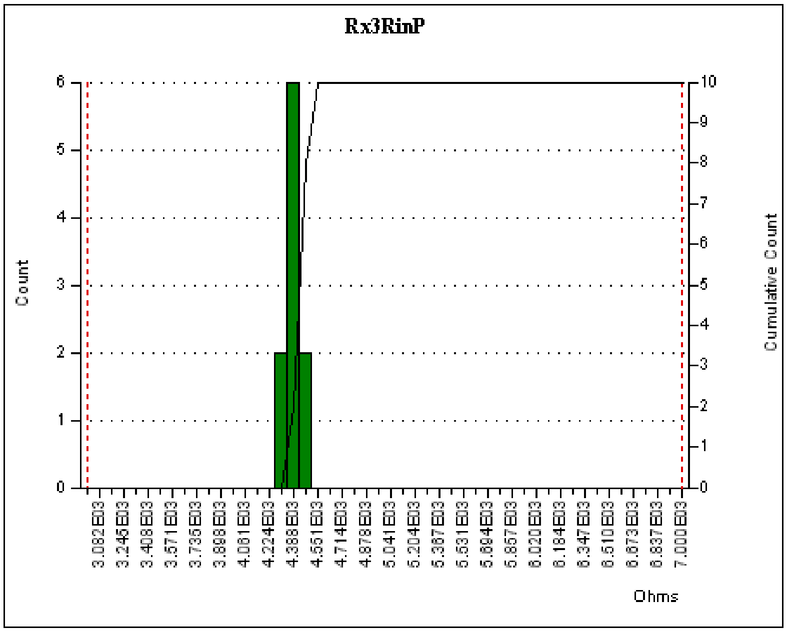
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=30.0, Test.Name=Rx3RinP



Statistics: (Ohms)

Max	4.453E03	**25%**	4.369E03	**SpecHigh**	7.000E03
Mean	4.388E03	**10%**	4.330E03	**SpecLow**	3.000E03
Min	4.321E03	**N**	10	**PctWithinSpec**	100.00
Range	132.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	39.886	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9821	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9755	**Cpk**	>4.0000		
90%	4.442E03	**Skew**	-0.1243		
75%	4.406E03	**Kurtosis**	-0.2105		
Median	4.391E03				

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

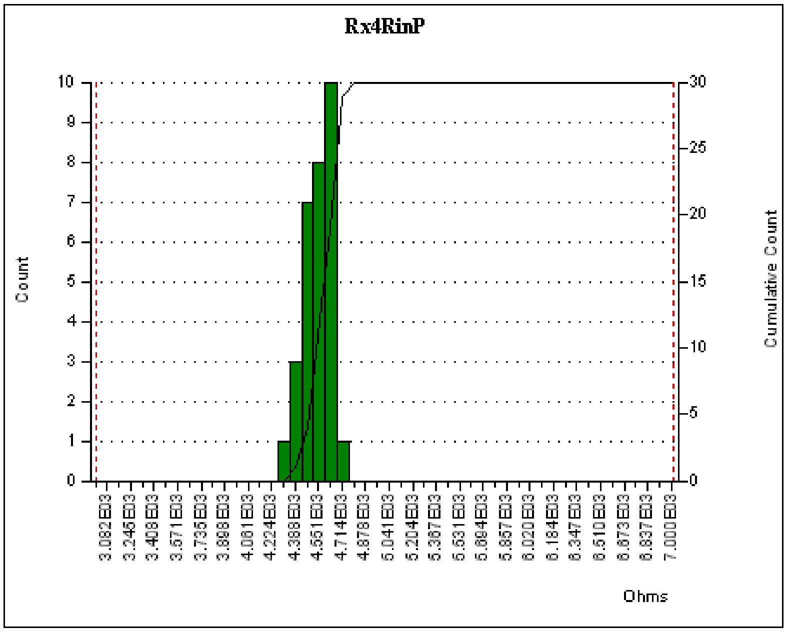
Stat limits applied

StatHigh	**StatLow**	**PctWithinStat**	**PctDefStat**	**NWithinStat**	**NOutsideStat**
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=31.0, Test.Name=Rx4RinP



Statistics: (Ohms)

Max	4.682E03	**25%**	4.492E03	**SpecHigh**	7.000E03
Mean	4.541E03	**10%**	4.407E03	**SpecLow**	3.000E03
Min	4.327E03	**N**	30	**PctWithinSpec**	100.00
Range	355.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	84.358	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9522	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1940	**Cpk**	>4.0000		
90%	4.627E03	**Skew**	-0.7260		
75%	4.608E03	**Kurtosis**	0.1039		
Median	4.562E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

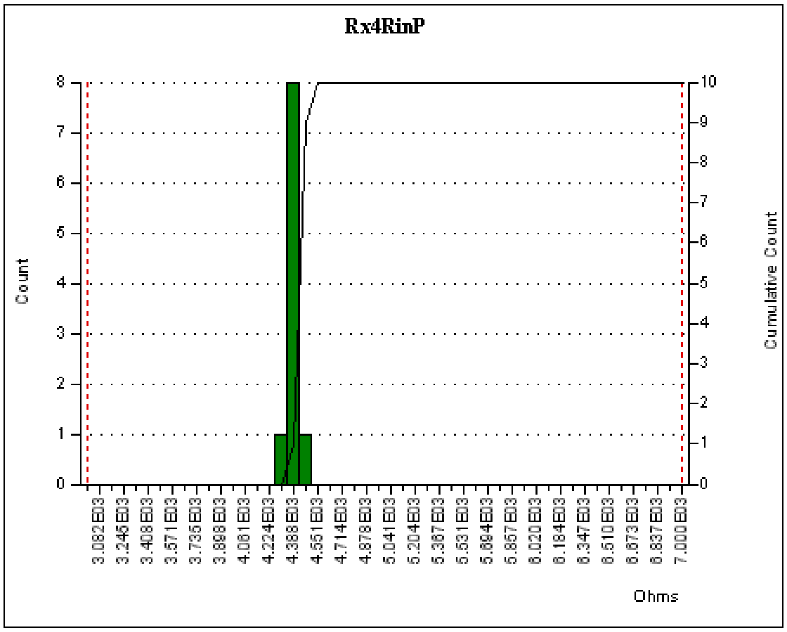
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=31.0, Test.Name=Rx4RinP



Statistics: (Ohms)

Max	4.442E03	**25%**	4.372E03	**SpecHigh**	7.000E03
Mean	4.388E03	**10%**	4.336E03	**SpecLow**	3.000E03
Min	4.323E03	**N**	10	**PctWithinSpec**	100.00
Range	119.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	35.987	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9771	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9478	**Cpk**	>4.0000		
90%	4.433E03	**Skew**	-0.3594		
75%	4.414E03	**Kurtosis**	-0.3005		
Median	4.388E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

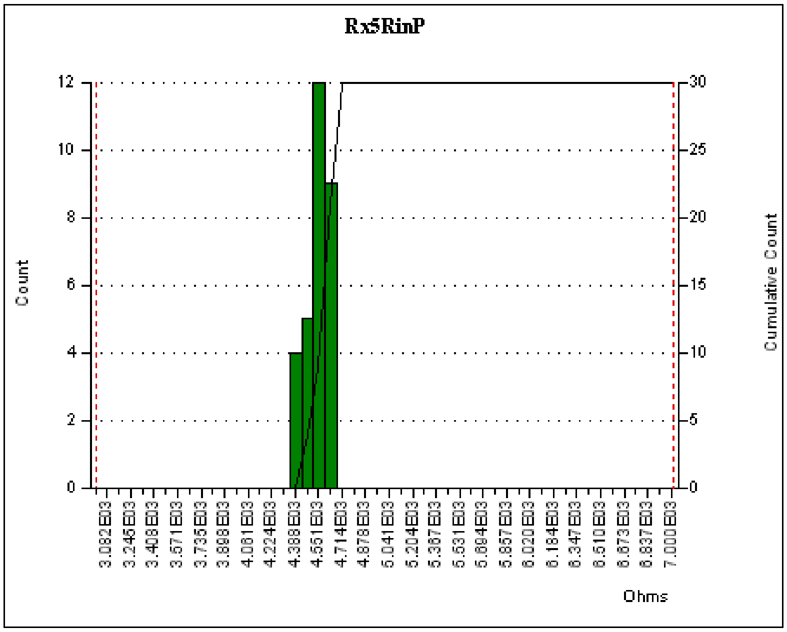
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=32.0, Test.Name=Rx5RinP



Statistics: (Ohms)

Max	4.672E03	**25%**	4.494E03	**SpecHigh**	7.000E03
Mean	4.536E03	**10%**	4.403E03	**SpecLow**	3.000E03
Min	4.347E03	**N**	30	**PctWithinSpec**	100.00
Range	325.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	79.710	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9501	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1701	**Cpk**	>4.0000		
90%	4.616E03	**Skew**	-0.6712		
75%	4.599E03	**Kurtosis**	-0.0593		
Median	4.548E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

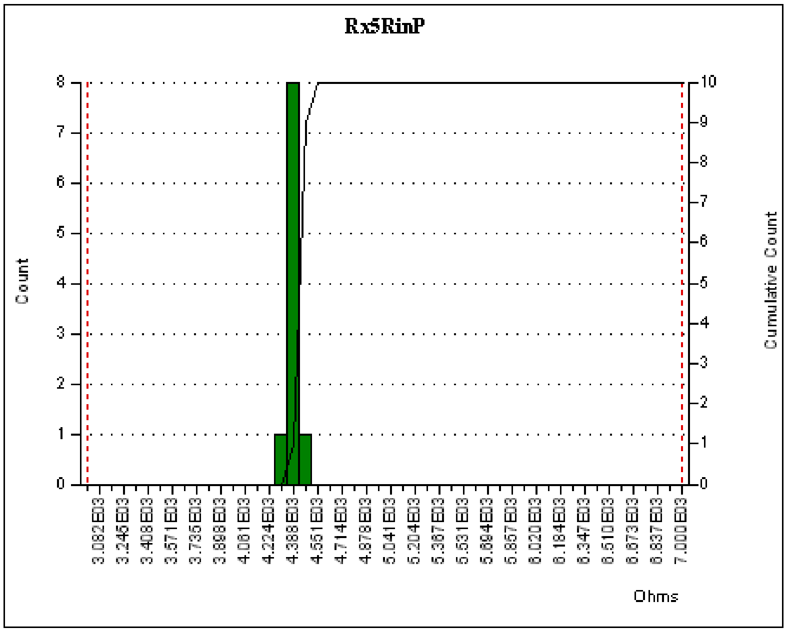
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=32.0, Test.Name=Rx5RinP



Statistics: (Ohms)

Max	4.451E03	**25%**	4.368E03	**SpecHigh**	7.000E03
Mean	4.386E03	**10%**	4.338E03	**SpecLow**	3.000E03
Min	4.319E03	**N**	10	**PctWithinSpec**	100.00
Range	132.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	36.578	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9864	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9902	**Cpk**	>4.0000		
90%	4.437E03	**Skew**	0.0181		
75%	4.407E03	**Kurtosis**	0.6615		
Median	4.383E03				

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

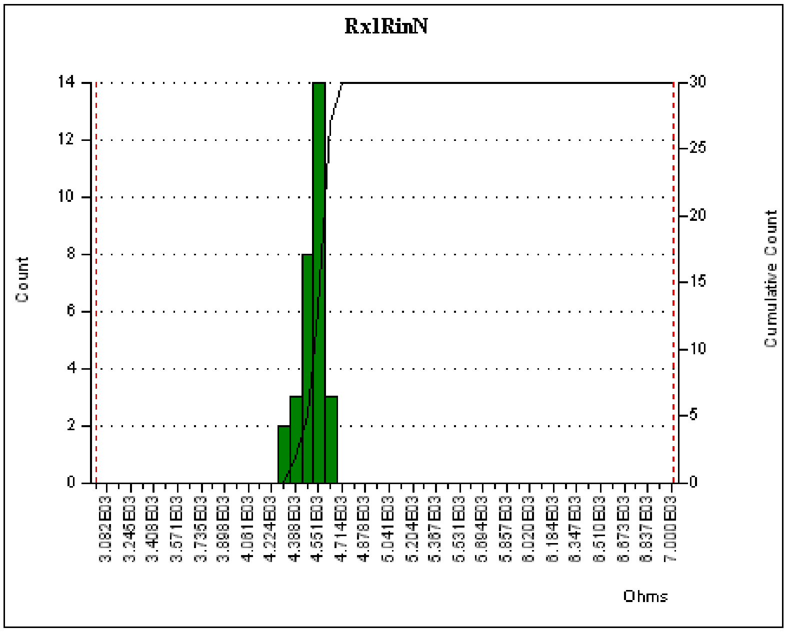
Stat limits applied

StatHigh	**StatLow**	**PctWithinStat**	**PctDefStat**	**NWithinStat**	**NOutsideStat**
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=33.0, Test.Name=Rx1RinN



Statistics: (Ohms)

Max	4.637E03	**25%**	4.468E03	**SpecHigh**	7.000E03
Mean	4.508E03	**10%**	4.370E03	**SpecLow**	3.000E03
Min	4.292E03	**N**	30	**PctWithinSpec**	100.00
Range	345.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	85.948	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9265	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.0398	**Cpk**	>4.0000		
90%	4.591E03	**Skew**	-0.8715		
75%	4.575E03	**Kurtosis**	0.1230		
Median	4.530E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

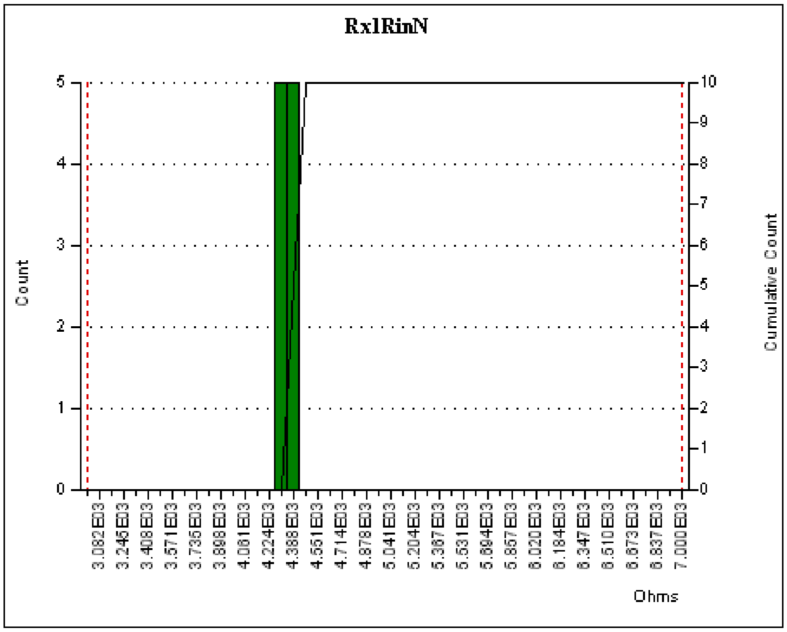
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=33.0, Test.Name=Rx1RinN



Statistics: (Ohms)

Max	4.408E03	**25%**	4.339E03	**SpecHigh**	7.000E03
Mean	4.352E03	**10%**	4.301E03	**SpecLow**	3.000E03
Min	4.289E03	**N**	10	**PctWithinSpec**	100.00
Range	119.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	34.663	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9832	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9802	**Cpk**	>4.0000		
90%	4.395E03	**Skew**	-0.3063		
75%	4.377E03	**Kurtosis**	0.0772		
Median	4.353E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

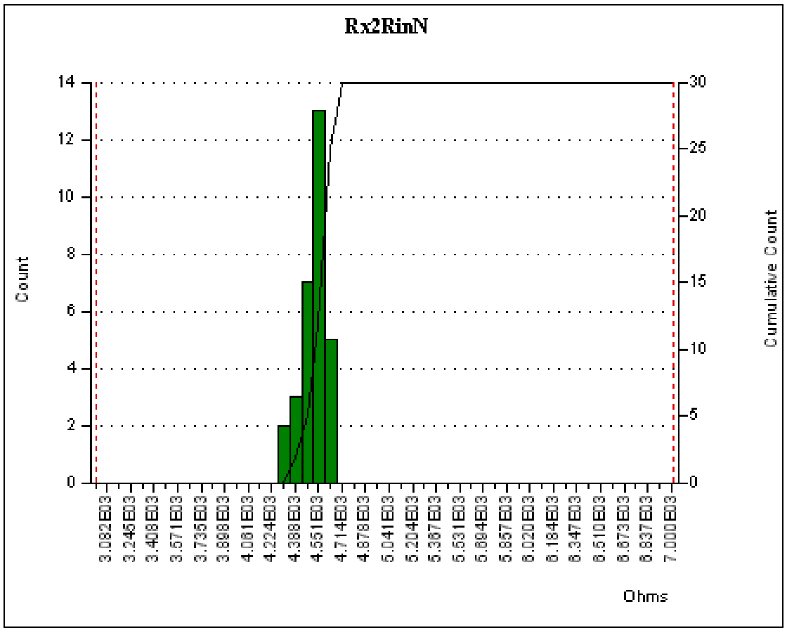
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=34.0, Test.Name=Rx2RinN



Statistics: (Ohms)

Max	4.661E03	**25%**	4.468E03	**SpecHigh**	7.000E03
Mean	4.514E03	**10%**	4.380E03	**SpecLow**	3.000E03
Min	4.290E03	**N**	30	**PctWithinSpec**	100.00
Range	371.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	92.863	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9502	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1716	**Cpk**	>4.0000		
90%	4.617E03	**Skew**	-0.7762		
75%	4.573E03	**Kurtosis**	0.4149		
Median	4.530E03				

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

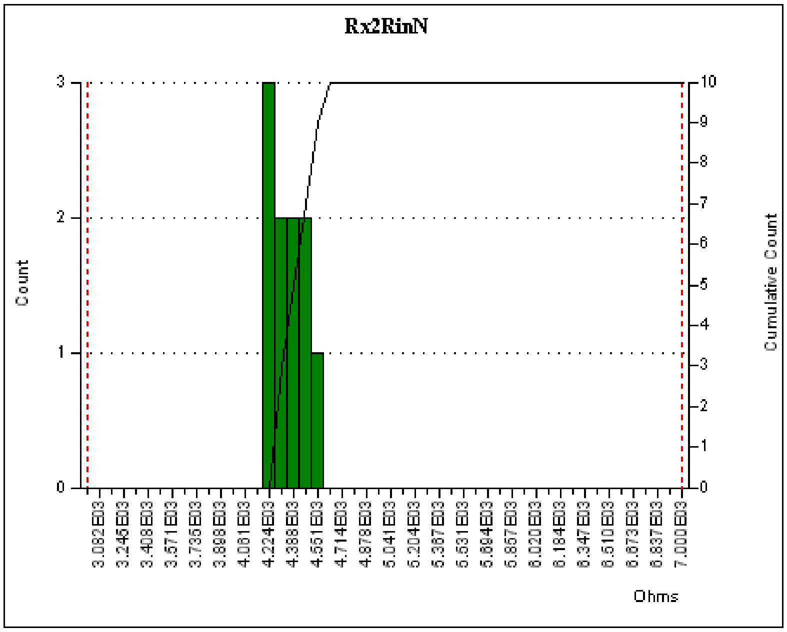
Stat limits applied

StatHigh	**StatLow**	**PctWithinStat**	**PctDefStat**	**NWithinStat**	**NOutsideStat**
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=34.0, Test.Name=Rx2RinN



Statistics: (Ohms)

Max	4.534E03	**25%**	4.255E03	**SpecHigh**	7.000E03
Mean	4.348E03	**10%**	4.224E03	**SpecLow**	3.000E03
Min	4.206E03	**N**	10	**PctWithinSpec**	100.00
Range	328.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	108.952	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9436	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.5937	**Cpk**	>4.0000		
90%	4.502E03	**Skew**	0.4702		
75%	4.458E03	**Kurtosis**	-0.9643		
Median	4.335E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

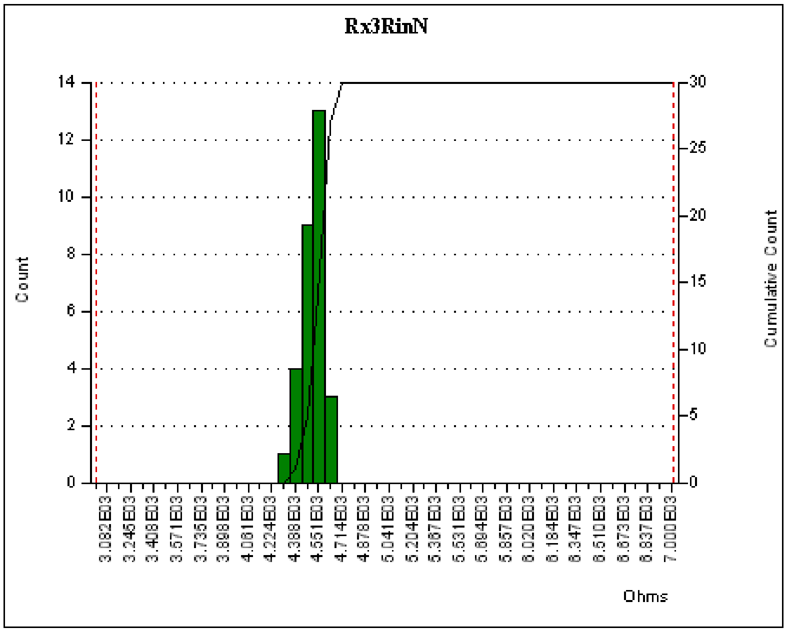
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=35.0, Test.Name=Rx3RinN



Statistics: (Ohms)

Max	4.642E03	**25%**	4.462E03	**SpecHigh**	7.000E03
Mean	4.507E03	**10%**	4.377E03	**SpecLow**	3.000E03
Min	4.297E03	**N**	30	**PctWithinSpec**	100.00
Range	345.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	83.011	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9469	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1399	**Cpk**	>4.0000		
90%	4.590E03	**Skew**	-0.7621		
75%	4.574E03	**Kurtosis**	0.1635		
Median	4.528E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

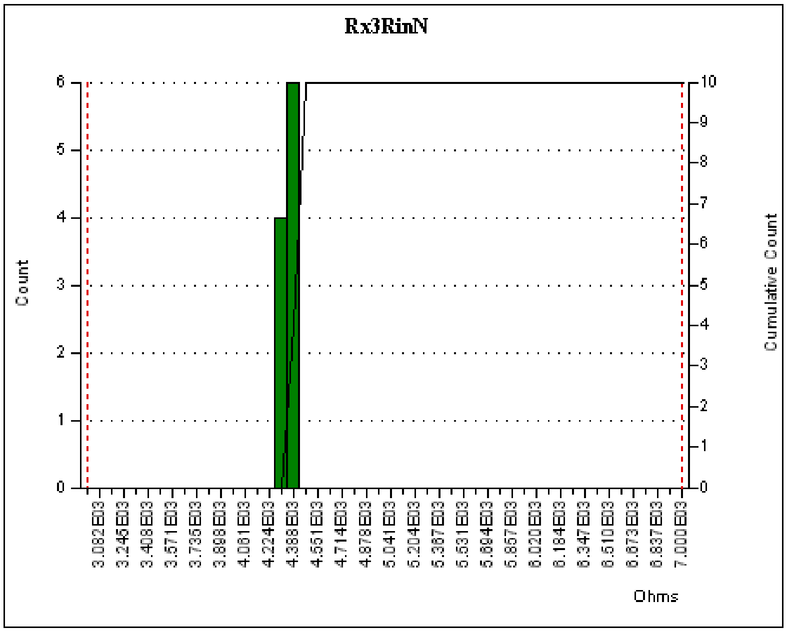
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=35.0, Test.Name=Rx3RinN



Statistics: (Ohms)

Max	4.424E03	**25%**	4.340E03	**SpecHigh**	7.000E03
Mean	4.357E03	**10%**	4.300E03	**SpecLow**	3.000E03
Min	4.291E03	**N**	10	**PctWithinSpec**	100.00
Range	133.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	39.725	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9815	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9728	**Cpk**	>4.0000		
90%	4.412E03	**Skew**	-0.0769		
75%	4.375E03	**Kurtosis**	-0.1137		
Median	4.359E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

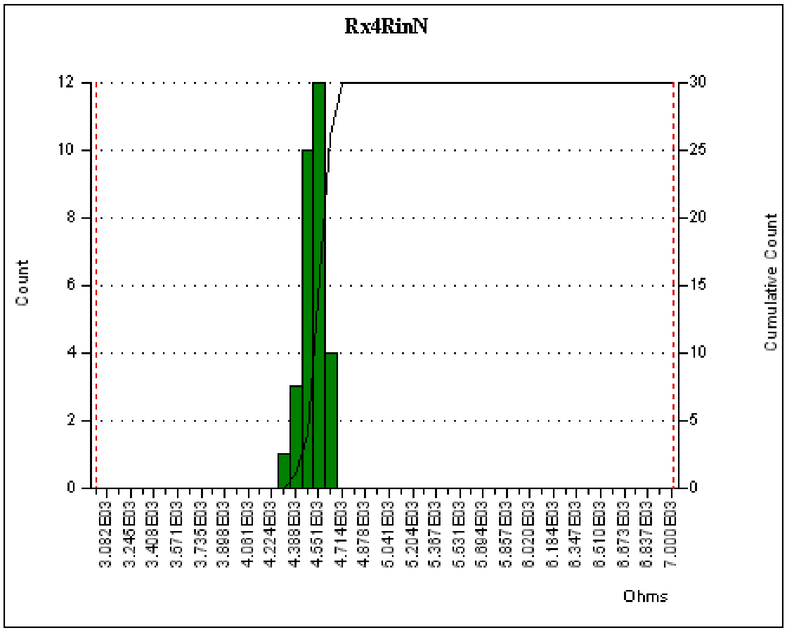
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=36.0, Test.Name=Rx4RinN



Statistics: (Ohms)

Max	4.650E03	**25%**	4.461E03	**SpecHigh**	7.000E03
Mean	4.509E03	**10%**	4.375E03	**SpecLow**	3.000E03
Min	4.297E03	**N**	30	**PctWithinSpec**	100.00
Range	353.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	83.764	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9508	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1776	**Cpk**	>4.0000		
90%	4.593E03	**Skew**	-0.7311		
75%	4.574E03	**Kurtosis**	0.1092		
Median	4.531E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

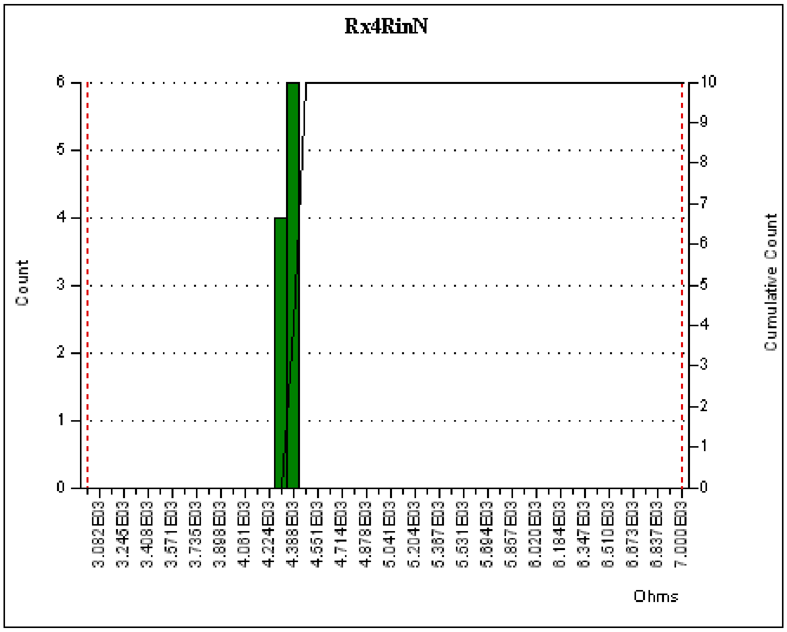
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=36.0, Test.Name=Rx4RinN



Statistics: (Ohms)

Max	4.410E03	**25%**	4.340E03	**SpecHigh**	7.000E03
Mean	4.357E03	**10%**	4.306E03	**SpecLow**	3.000E03
Min	4.294E03	**N**	10	**PctWithinSpec**	100.00
Range	116.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	35.197	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9793	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9614	**Cpk**	>4.0000		
90%	4.401E03	**Skew**	-0.3009		
75%	4.381E03	**Kurtosis**	-0.3877		
Median	4.357E03				

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

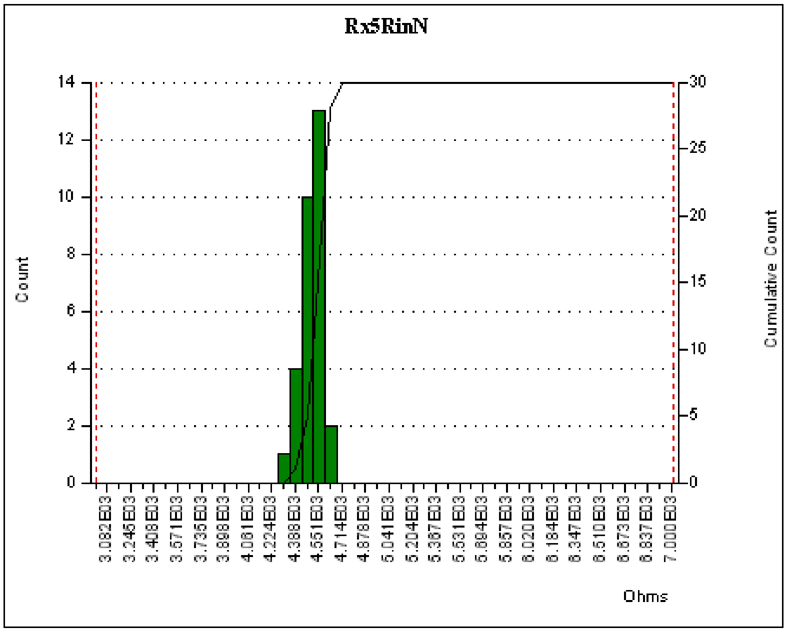
Stat limits applied

StatHigh	**StatLow**	**PctWithinStat**	**PctDefStat**	**NWithinStat**	**NOutsideStat**
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=37.0, Test.Name=Rx5RinN



Statistics: (Ohms)

Max	4.638E03	**25%**	4.463E03	**SpecHigh**	7.000E03
Mean	4.503E03	**10%**	4.372E03	**SpecLow**	3.000E03
Min	4.315E03	**N**	30	**PctWithinSpec**	100.00
Range	323.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	78.901	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9487	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1564	**Cpk**	>4.0000		
90%	4.582E03	**Skew**	-0.6901		
75%	4.566E03	**Kurtosis**	-0.0078		
Median	4.516E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Hotchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

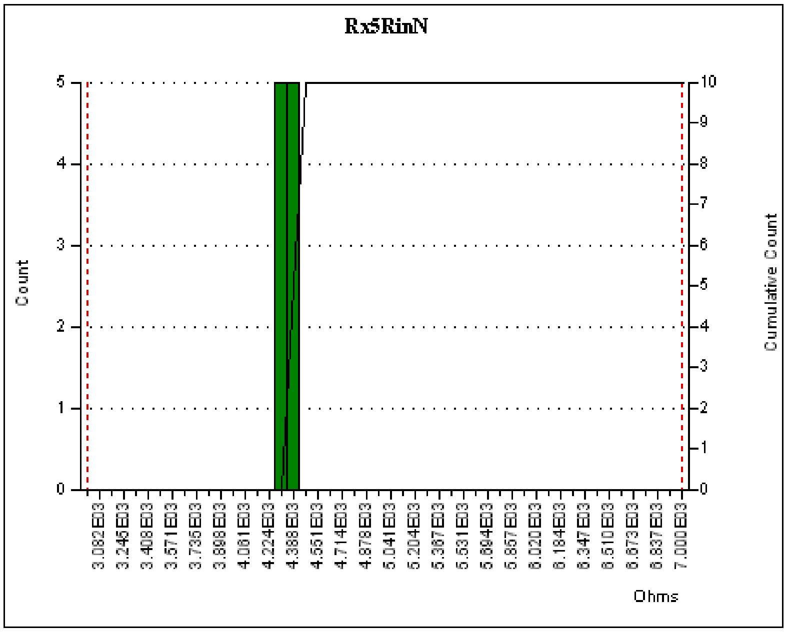
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=37.0, Test.Name=Rx5RinN



Statistics: (Ohms)

Max	4.417E03	**25%**	4.337E03	**SpecHigh**	7.000E03
Mean	4.353E03	**10%**	4.306E03	**SpecLow**	3.000E03
Min	4.288E03	**N**	10	**PctWithinSpec**	100.00
Range	129.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	35.686	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9844	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.9843	**Cpk**	>4.0000		
90%	4.404E03	**Skew**	0.0372		
75%	4.374E03	**Kurtosis**	0.6936		
Median	4.351E03				

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
SP3243EBEA_0336_H: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
85C

Data: Raw Data

Stat limits applied

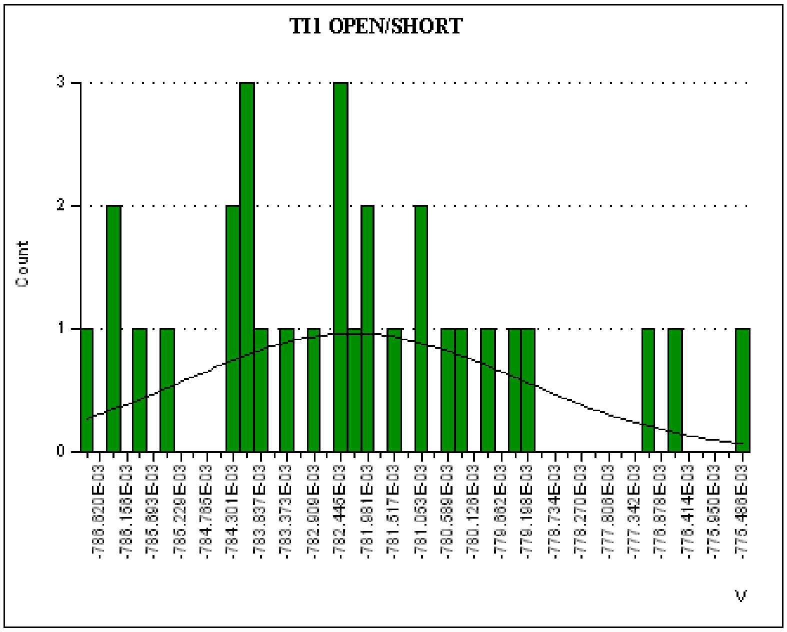
StatHigh	**StatLow**	**PctWithinStat**	**PctDefStat**	**NWithinStat**	**NOutsideStat**
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Thu 30 Mar 2006, 12:26 PM

Test.Number=1.000, Test.Name=TI1 OPEN/SHORT



Statistics: (V)

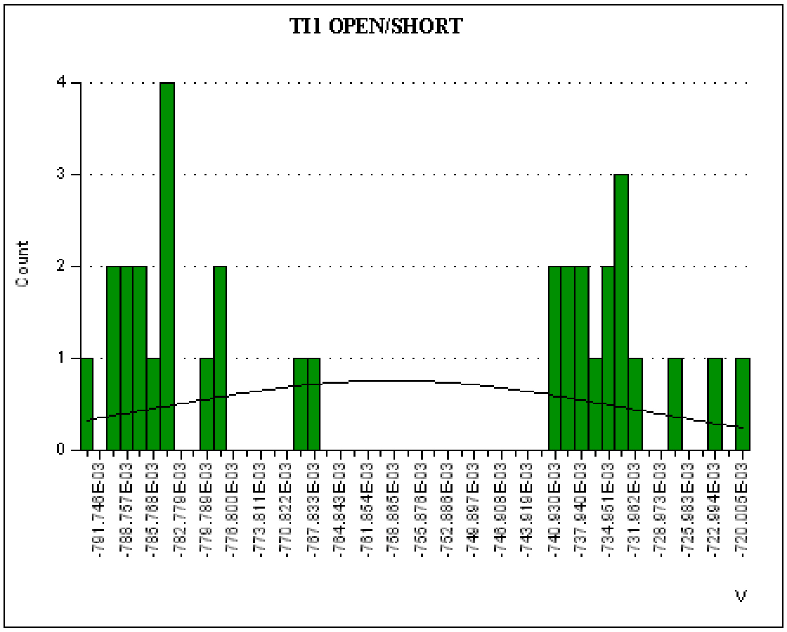
Min	-786.852E-03	**Skew**	0.5529
Max	-775.486E-03	**StatHigh**	N/A
Mean	-782.271E-03	**StatLow**	N/A
StdDev	2.887E-03	**NWithinSpec**	N/A
25%	-784.181E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-773.610E-03	**90%**	-778.118E-03
		Range	11.366E-03
Mean-3*StdDev	-790.931E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=1.000, Test.Name=TI1 OPEN/SHORT



Statistics: (V)

Min	-793.241E-03	**StatLow**	N/A
Max	-720.005E-03	**NWithinSpec**	N/A
Mean	-759.529E-03	**NOutsideSpec**	N/A
StdDev	25.928E-03	**90%**	-731.893E-03
25%	-784.831E-03	**Range**	73.236E-03
Mean+3*StdDev	-681.744E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-837.313E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.0458		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

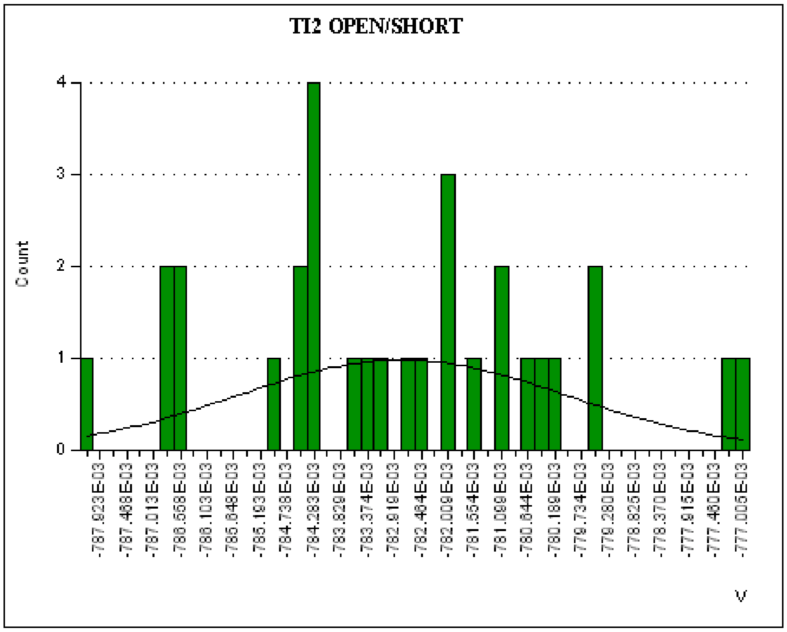
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=1.001, Test.Name=TI2 OPEN/SHORT



Statistics: (V)

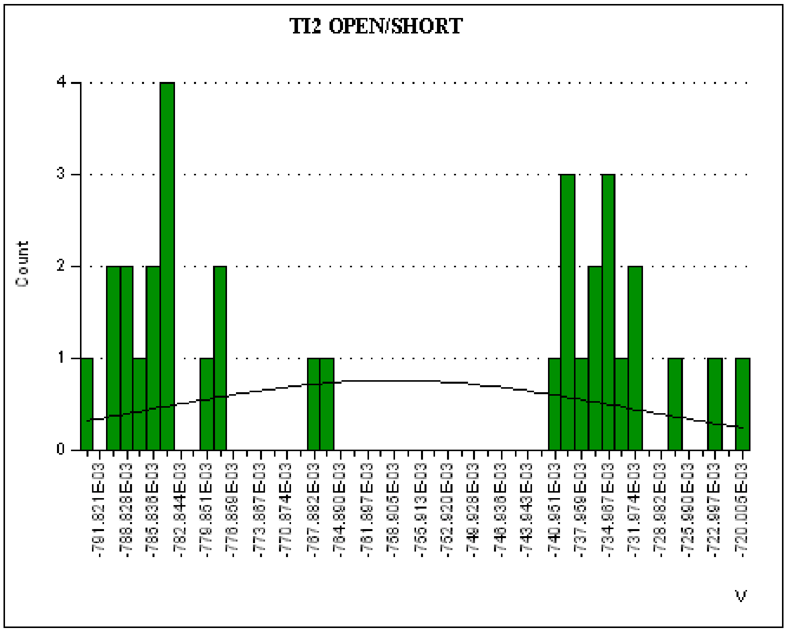
Min	-788.150E-03	**Skew**	0.2054
Max	-777.005E-03	**StatHigh**	N/A
Mean	-782.837E-03	**StatLow**	N/A
StdDev	2.761E-03	**NWithinSpec**	N/A
25%	-784.410E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-774.555E-03	**90%**	-779.448E-03
		Range	11.145E-03
Mean-3*StdDev	-791.119E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=1.001, Test.Name=TI2 OPEN/SHORT



Statistics: (V)

Min	-793.317E-03	**StatLow**	N/A
Max	-720.005E-03	**NWithinSpec**	N/A
Mean	-759.451E-03	**NOutsideSpec**	N/A
StdDev	25.815E-03	**90%**	-732.044E-03
25%	-784.797E-03	**Range**	73.312E-03
Mean+3*StdDev	-682.006E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-836.895E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0427		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

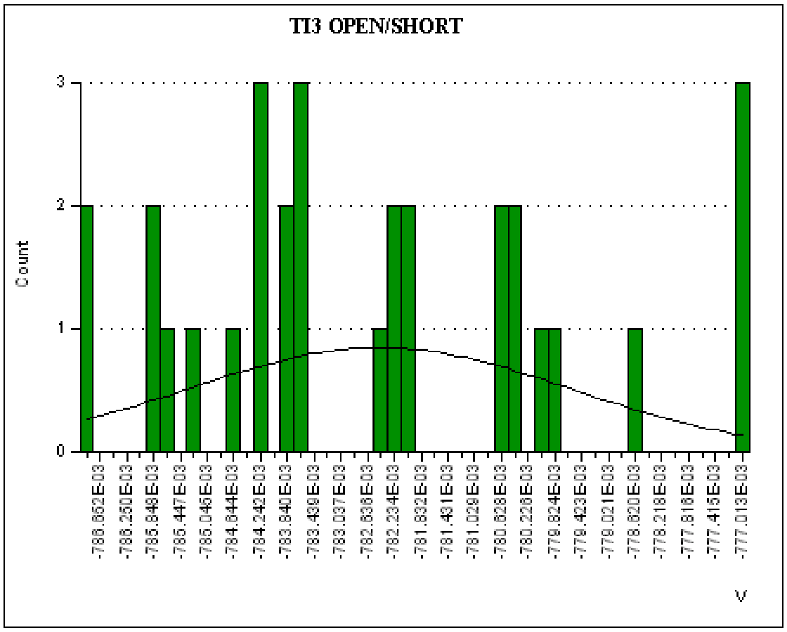
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=1.002, Test.Name=TI3 OPEN/SHORT



Statistics: (V)

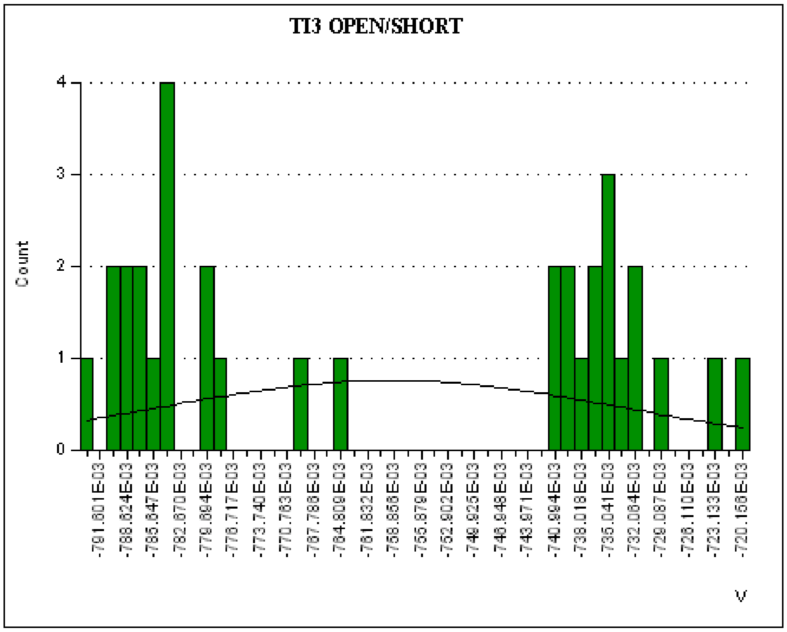
Min	-786.852E-03	**Skew**	0.4573
Max	-777.013E-03	**StatHigh**	N/A
Mean	-782.504E-03	**StatLow**	N/A
StdDev	2.830E-03	**NWithinSpec**	N/A
25%	-784.333E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-774.016E-03	**90%**	-777.887E-03
		Range	9.839E-03
Mean-3*StdDev	-790.993E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=1.002, Test.Name=TI3 OPEN/SHORT



Statistics: (V)

Min	-793.089E-03	**StatLow**	N/A
Max	-720.156E-03	**NWithinSpec**	N/A
Mean	-759.614E-03	**NOutsideSpec**	N/A
StdDev	25.722E-03	**90%**	-732.196E-03
25%	-784.831E-03	**Range**	72.933E-03
Mean+3*StdDev	-682.448E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-836.779E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.0371		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

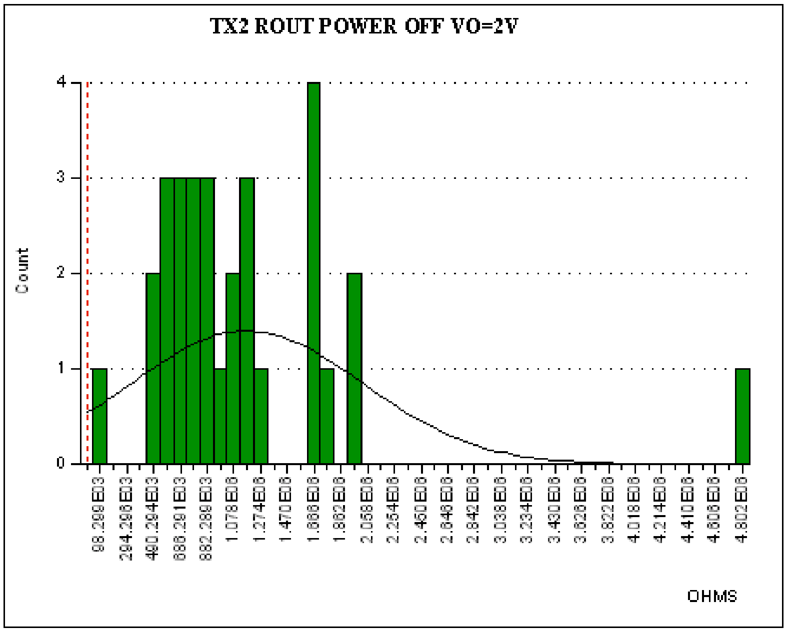
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=2.001, Test.Name=TX2 ROUT POWER OFF VO=2V



Statistics: (OHMS)

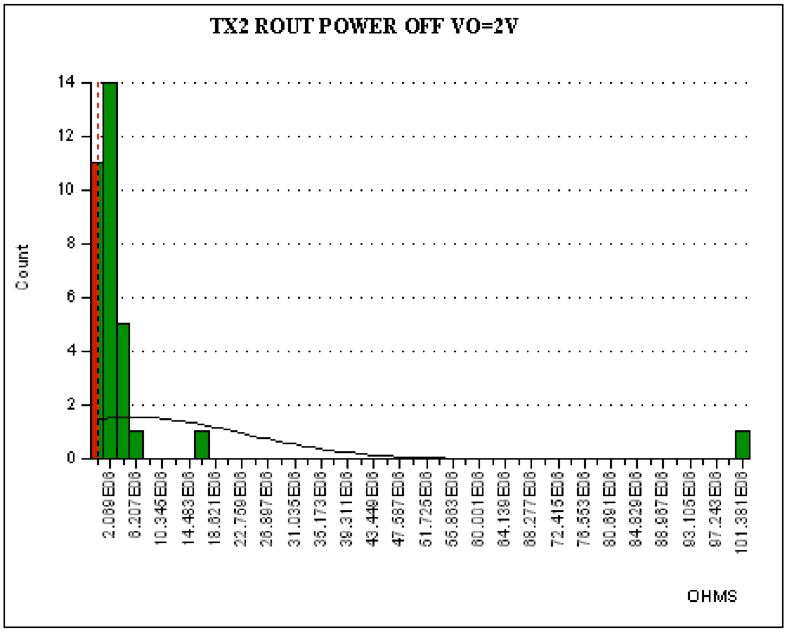
Min	62.091E03	**Skew**	2.9373
Max	4.802E06	**StatHigh**	N/A
Mean	1.162E06	**StatLow**	N/A
StdDev	839.544E03	**NWithinSpec**	30
25%	668.344E03	**NOutsideSpec**	0
Mean+3*StdDev	3.680E06	**90%**	1.843E06
		Range	4.740E06
Mean-3*StdDev	-1.357E06	**NOutsideSpec**	0
Cpk	0.4611		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.001, Test.Name=TX2 ROUT POWER OFF VO=2V



Statistics: (OHMS)

Min	56.132E03	**StatLow**	N/A
Max	101.381E06	**NWithinSpec**	33
Mean	5.259E06	**NOutsideSpec**	0
StdDev	17.497E06	**90%**	4.722E06
25%	870.859E03	**Range**	101.325E06
Mean+3*StdDev	57.749E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-47.232E06	**Cpl**	0.1002
		Cpu	N/A
Cpk	0.1002		
Skew	5.5136		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

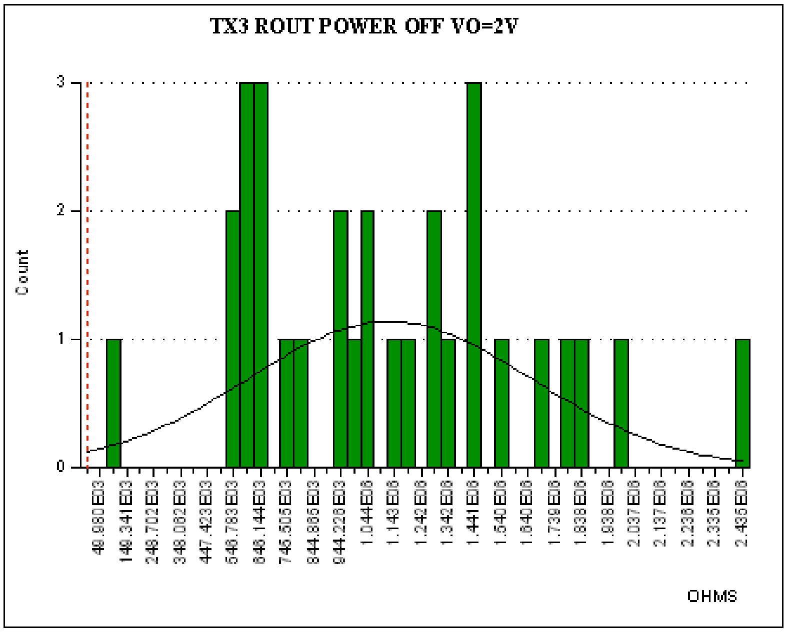
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=2.002, Test.Name=TX3 ROUT POWER OFF VO=2V



Statistics: (OHMS)

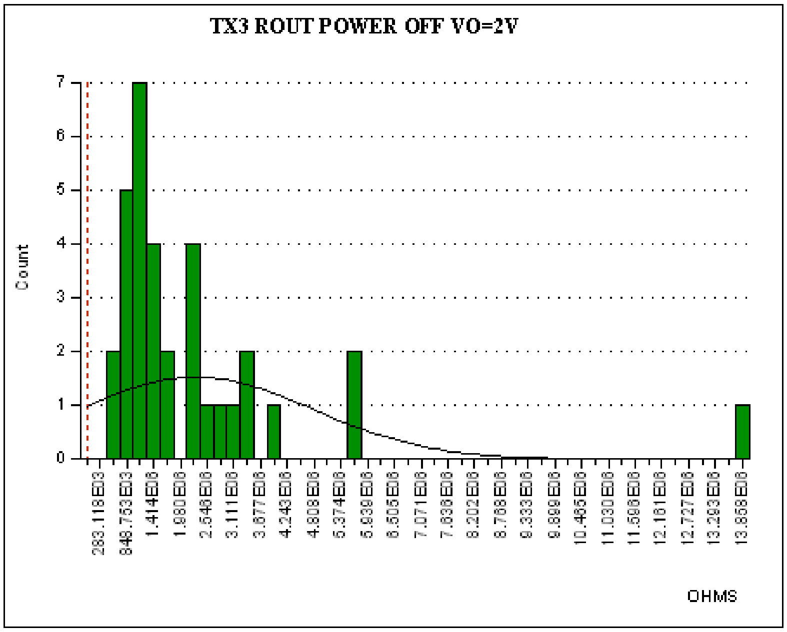
Min	95.177E03	**Skew**	0.4871
Max	2.435E06	**StatHigh**	N/A
Mean	1.113E06	**StatLow**	N/A
StdDev	522.383E03	**NWithinSpec**	30
25%	630.864E03	**NOutsideSpec**	0
Mean+3*StdDev	2.680E06	**90%**	1.807E06
		Range	2.339E06
Mean-3*StdDev	-453.805E03	**NOutsideSpec**	0
Cpk	0.7102		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.002, Test.Name=TX3 ROUT POWER OFF VO=2V



Statistics: (OHMS)

Min	644.597E03	**StatLow**	N/A
Max	13.858E06	**NWithinSpec**	33
Mean	2.290E06	**NOutsideSpec**	0
StdDev	2.439E06	**90%**	3.825E06
25%	1.040E06	**Range**	13.214E06
Mean+3*StdDev	9.607E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-5.026E06	**Cpl**	0.3130
		Cpu	N/A
Cpk	0.3130		
Skew	3.6353		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

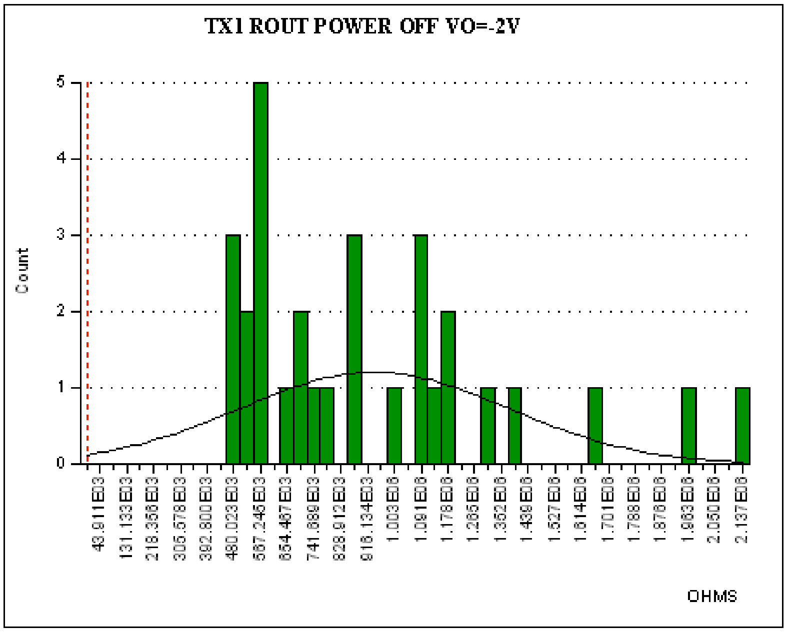
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=2.003, Test.Name=TX1 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

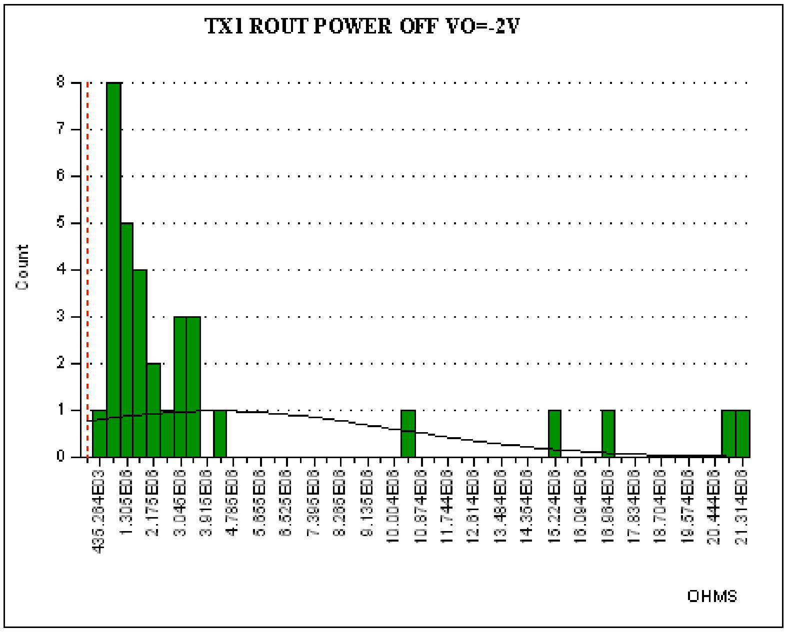
Min	466.422E03	**Skew**	1.2479
Max	2.137E06	**StatHigh**	N/A
Mean	929.099E03	**StatLow**	N/A
StdDev	432.957E03	**NWithinSpec**	30
25%	571.339E03	**NOutsideSpec**	0
Mean+3*StdDev	2.228E06	**90%**	1.528E06
		Range	1.671E06
Mean-3*StdDev	-369.771E03	**NOutsideSpec**	0
Cpk	0.7151		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.003, Test.Name=TX1 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

Min	537.490E03	**StatLow**	N/A
Max	21.314E06	**NWithinSpec**	33
Mean	4.122E06	**NOutsideSpec**	0
StdDev	5.797E06	**90%**	15.187E06
25%	1.039E06	**Range**	20.776E06
Mean+3*StdDev	21.513E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-13.269E06	**Cpl**	0.2370
		Cpu	N/A
Cpk	0.2370		
Skew	2.2134		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

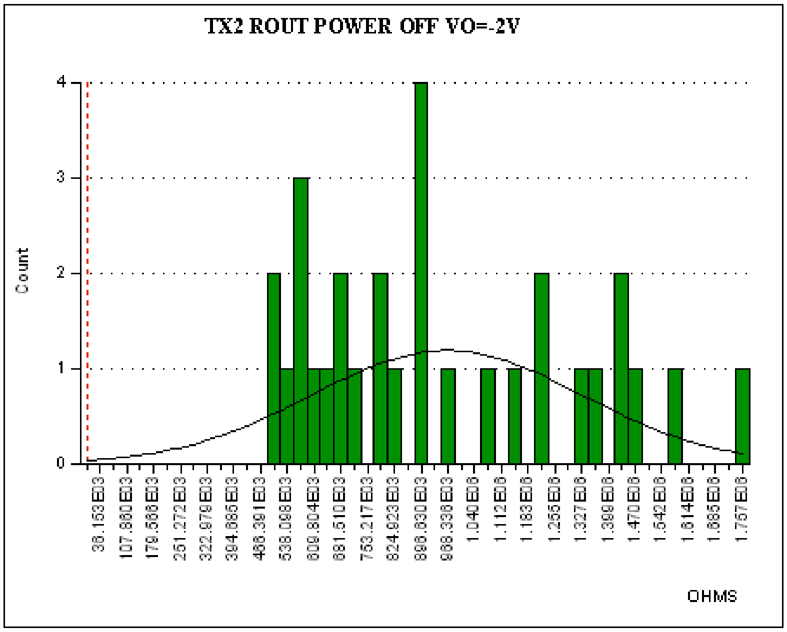
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=2.004, Test.Name=TX2 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

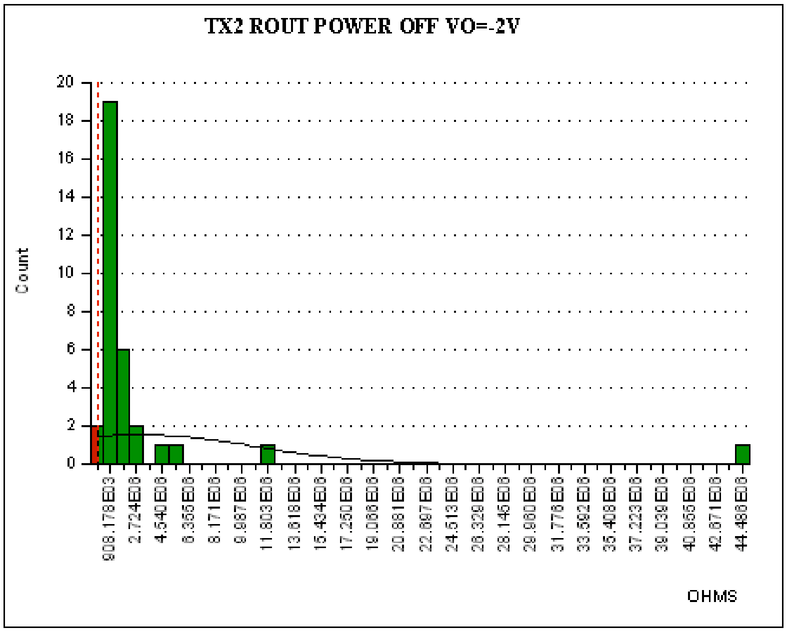
Min	494.238E03	**Skew**	0.5693
Max	1.757E06	**StatHigh**	N/A
Mean	955.454E03	**StatLow**	N/A
StdDev	359.984E03	**NWithinSpec**	30
25%	635.951E03	**NOutsideSpec**	0
Mean+3*StdDev	2.035E06	**90%**	1.463E06
		Range	1.263E06
Mean-3*StdDev	-124.498E03	**NOutsideSpec**	0
Cpk	0.8844		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.004, Test.Name=TX2 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

Min	373.039E03	**StatLow**	N/A
Max	44.486E06	**NWithinSpec**	33
Mean	2.979E06	**NOutsideSpec**	0
StdDev	7.740E06	**90%**	4.335E06
25%	699.942E03	**Range**	44.113E06
Mean+3*StdDev	26.198E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-20.241E06	**Cpl**	0.1283
Cpk	0.1283	**Cpu**	N/A
Skew	5.1618		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

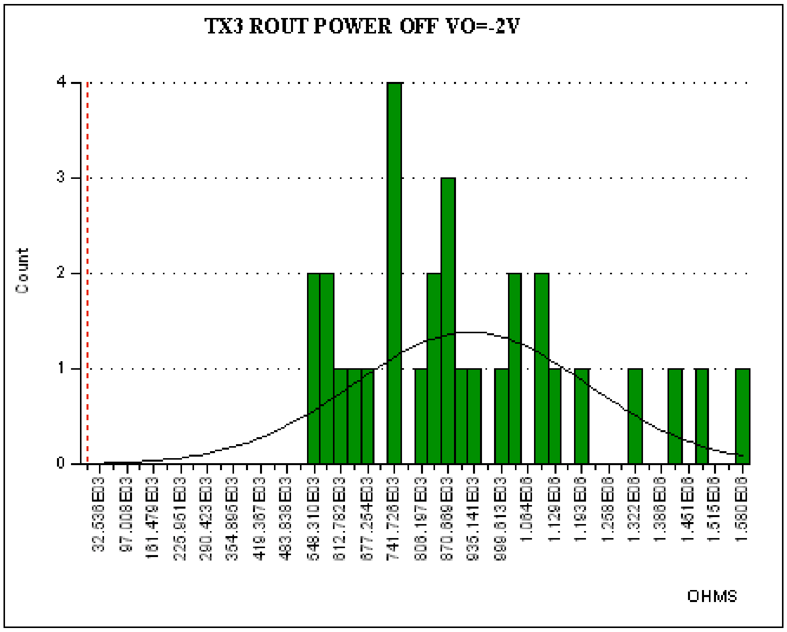
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=2.005, Test.Name=TX3 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

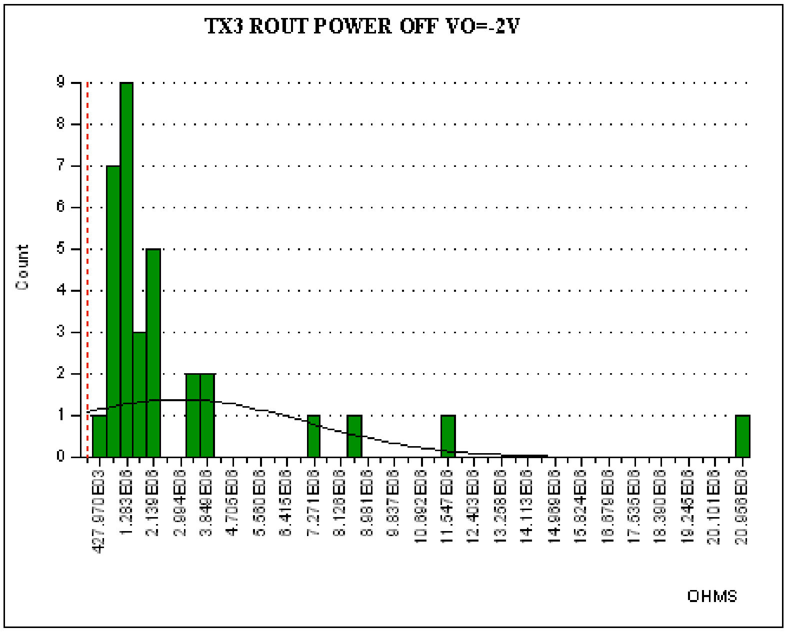
Min	549.415E03	**Skew**	0.7889
Max	1.580E06	**StatHigh**	N/A
Mean	914.523E03	**StatLow**	N/A
StdDev	278.342E03	**NWithinSpec**	30
25%	726.945E03	**NOutsideSpec**	0
Mean+3*StdDev	1.750E06	**90%**	1.369E06
		Range	1.030E06
Mean-3*StdDev	79.498E03	**NOutsideSpec**	0
Cpk	1.0948		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.005, Test.Name=TX3 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

Min	576.595E03	**StatLow**	N/A
Max	20.956E06	**NWithinSpec**	33
Mean	2.921E06	**NOutsideSpec**	0
StdDev	4.044E06	**90%**	7.351E06
25%	1.128E06	**Range**	20.380E06
Mean+3*StdDev	15.051E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-9.210E06	**Cpl**	0.2407
		Cpu	N/A
Cpk	0.2407		
Skew	3.3621		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

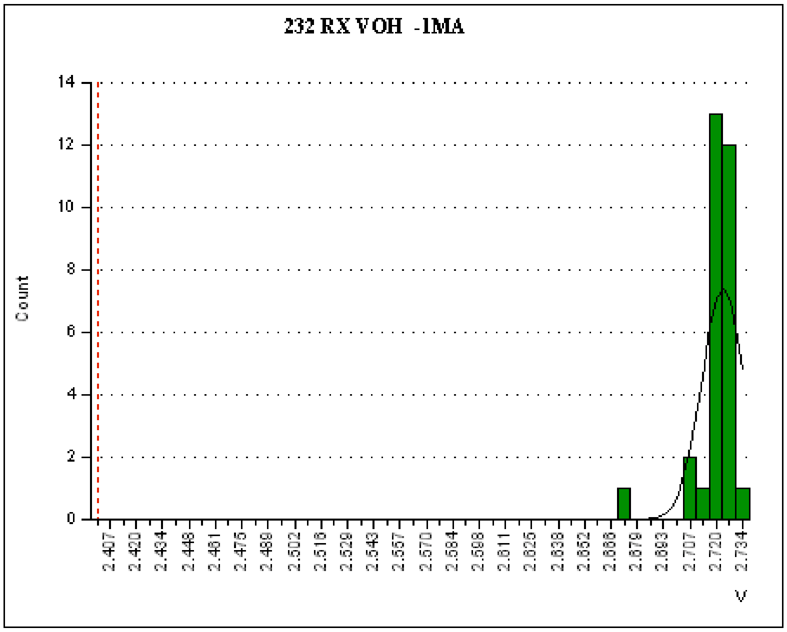
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.000, Test.Name=232 RX VOH -1MA



Statistics: (V)

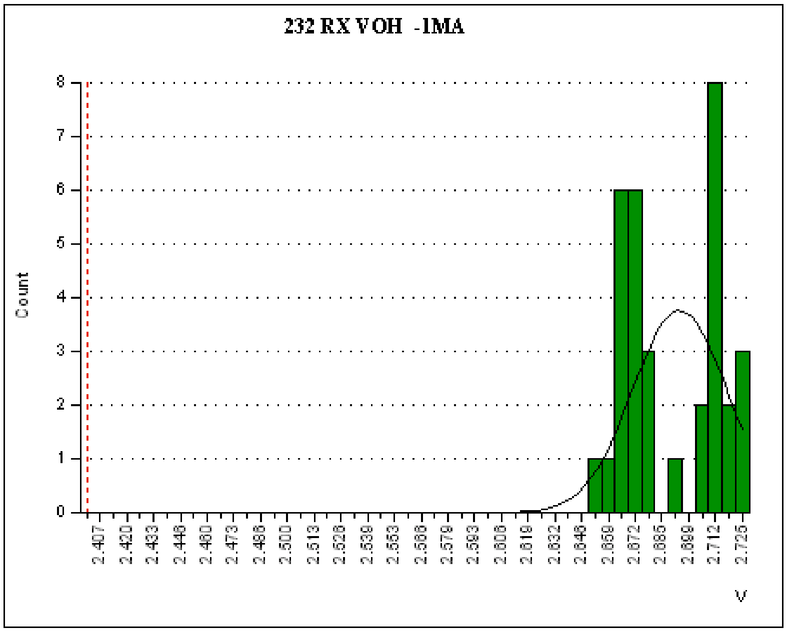
Min	2.670	**Skew**	-3.5096
Max	2.734	**StatHigh**	N/A
Mean	2.720	**StatLow**	N/A
StdDev	11.039E-03	**NWithinSpec**	30
25%	2.720	**NOutsideSpec**	0
Mean+3*StdDev	2.753	**90%**	2.727
		Range	64.080E-03
Mean-3*StdDev	2.687	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.000, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.654	**StatLow**	N/A
Max	2.725	**NWithinSpec**	33
Mean	2.691	**NOutsideSpec**	0
StdDev	23.206E-03	**90%**	2.718
25%	2.672	**Range**	70.882E-03
Mean+3*StdDev	2.761	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.621	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	0.0555		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

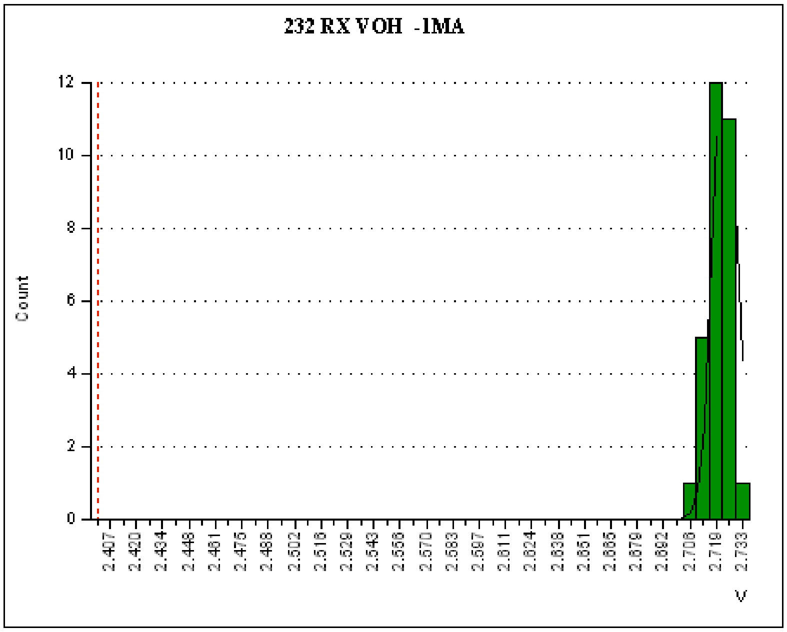
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.001, Test.Name=232 RX VOH -1MA



Statistics: (V)

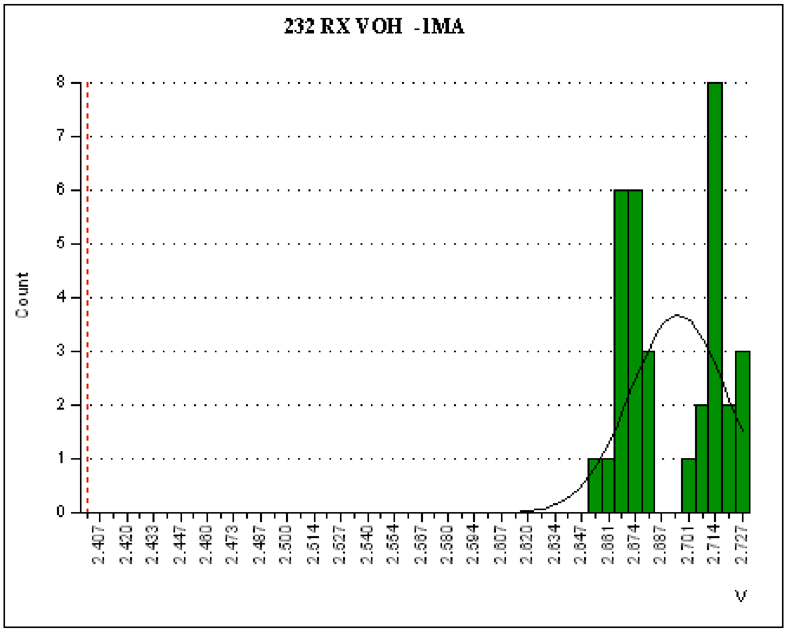
Min	2.708	**Skew**	-0.5064
Max	2.733	**StatHigh**	N/A
Mean	2.721	**StatLow**	N/A
StdDev	6.007E-03	**NWithinSpec**	30
25%	2.719	**NOutsideSpec**	0
Mean+3*StdDev	2.739	**90%**	2.727
		Range	24.989E-03
Mean-3*StdDev	2.703	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.001, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.653	**StatLow**	N/A
Max	2.727	**NWithinSpec**	33
Mean	2.692	**NOutsideSpec**	0
StdDev	23.895E-03	**90%**	2.720
25%	2.671	**Range**	74.416E-03
Mean+3*StdDev	2.764	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.620	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	0.0478		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

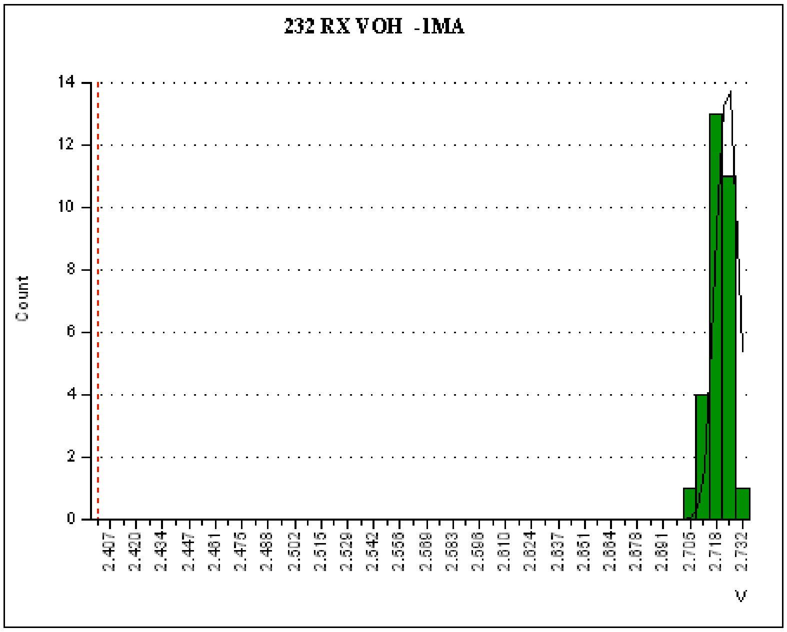
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.002, Test.Name=232 RX VOH -1MA



Statistics: (V)

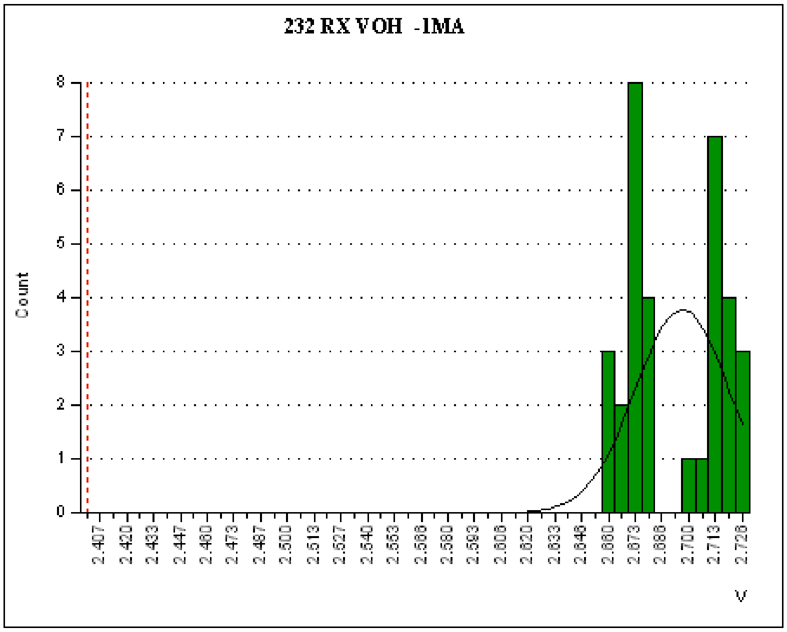
Min	2.705	**Skew**	-0.7128
Max	2.732	**StatHigh**	N/A
Mean	2.721	**StatLow**	N/A
StdDev	5.747E-03	**NWithinSpec**	30
25%	2.719	**NOutsideSpec**	0
Mean+3*StdDev	2.738	**90%**	2.727
		Range	26.602E-03
Mean-3*StdDev	2.703	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.002, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.657	**StatLow**	N/A
Max	2.726	**NWithinSpec**	33
Mean	2.693	**NOutsideSpec**	0
StdDev	23.211E-03	**90%**	2.722
25%	2.673	**Range**	68.879E-03
Mean+3*StdDev	2.763	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.623	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	0.0685		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

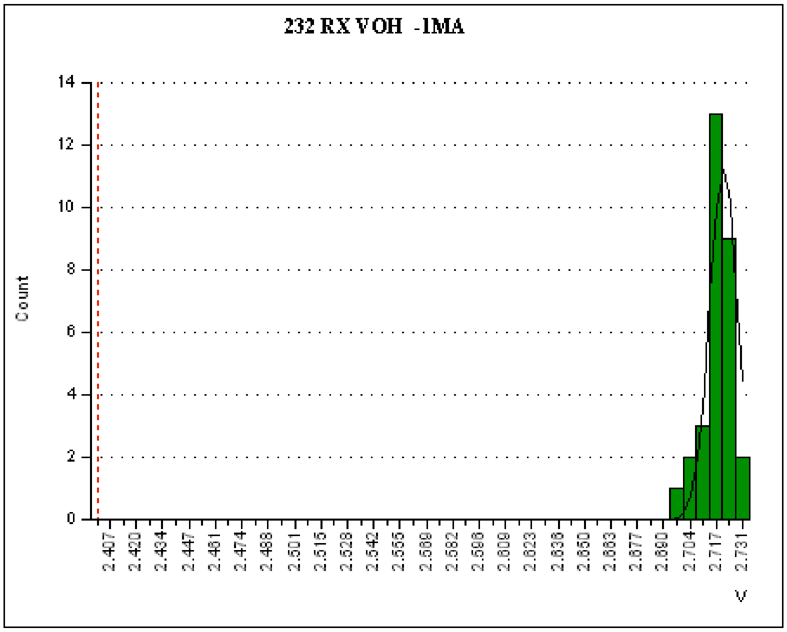
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.003, Test.Name=232 RX VOH -1MA



Statistics: (V)

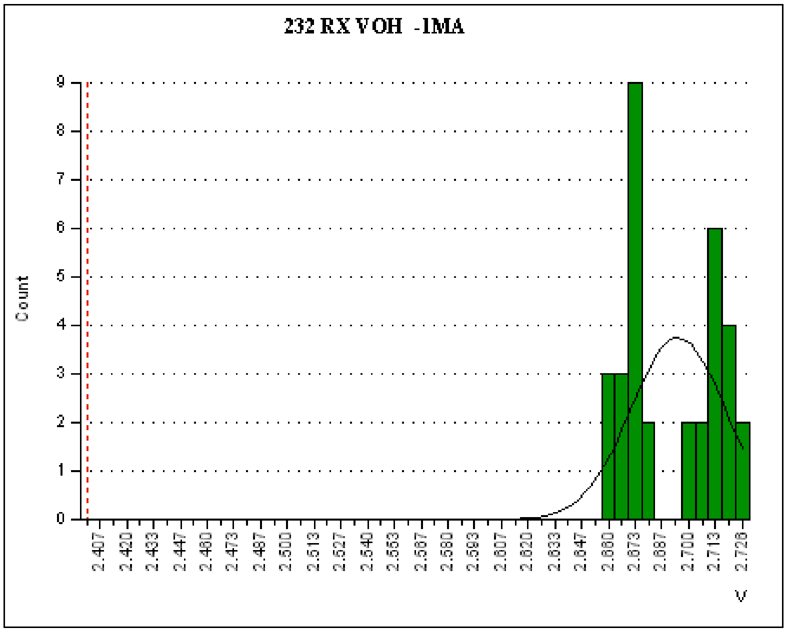
Min	2.698	**Skew**	-0.9945
Max	2.731	**StatHigh**	N/A
Mean	2.718	**StatLow**	N/A
StdDev	7.205E-03	**NWithinSpec**	30
25%	2.716	**NOutsideSpec**	0
Mean+3*StdDev	2.739	**90%**	2.725
		Range	32.561E-03
Mean-3*StdDev	2.696	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.003, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.657	**StatLow**	N/A
Max	2.726	**NWithinSpec**	33
Mean	2.691	**NOutsideSpec**	0
StdDev	23.395E-03	**90%**	2.720
25%	2.671	**Range**	69.674E-03
Mean+3*StdDev	2.761	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.621	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	0.0705		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

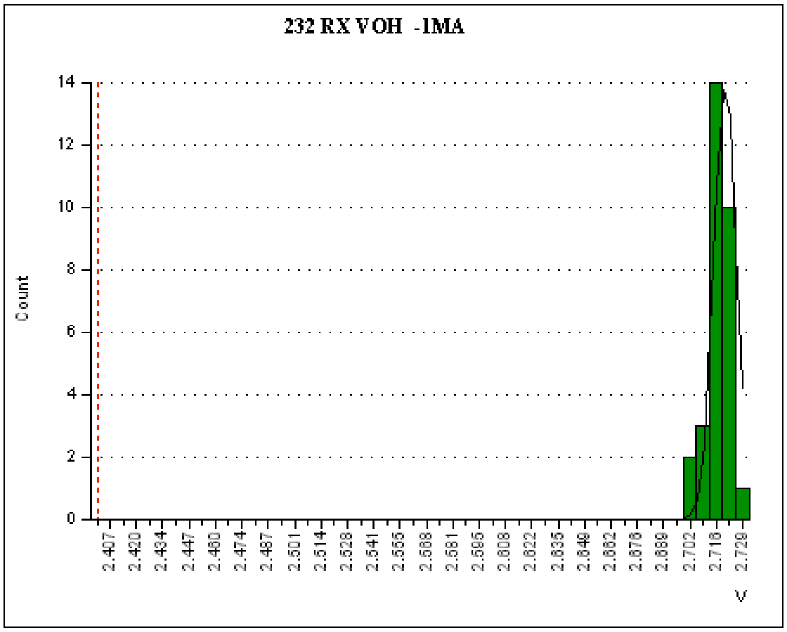
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.004, Test.Name=232 RX VOH -1MA



Statistics: (V)

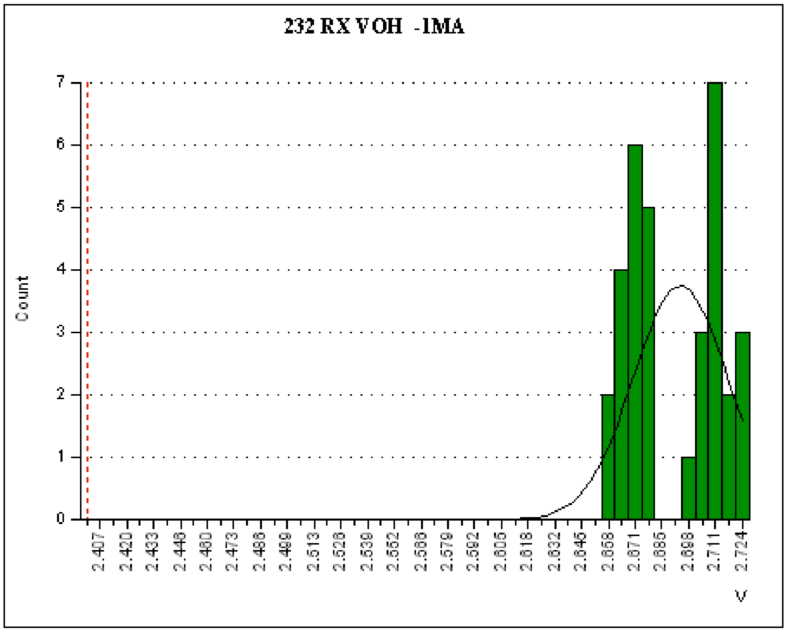
Min	2.704	**Skew**	-0.5009
Max	2.729	**StatHigh**	N/A
Mean	2.717	**StatLow**	N/A
StdDev	5.754E-03	**NWithinSpec**	30
25%	2.715	**NOutsideSpec**	0
Mean+3*StdDev	2.734	**90%**	2.723
		Range	25.510E-03
Mean-3*StdDev	2.700	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.004, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.655	**StatLow**	N/A
Max	2.724	**NWithinSpec**	33
Mean	2.691	**NOutsideSpec**	0
StdDev	23.259E-03	**90%**	2.720
25%	2.672	**Range**	69.051E-03
Mean+3*StdDev	2.760	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.621	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	0.0594		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

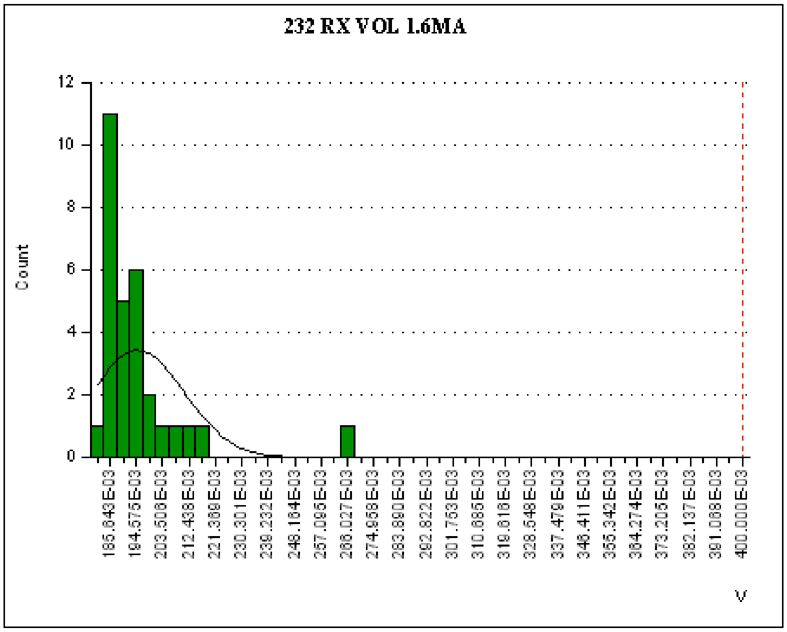
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.005, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

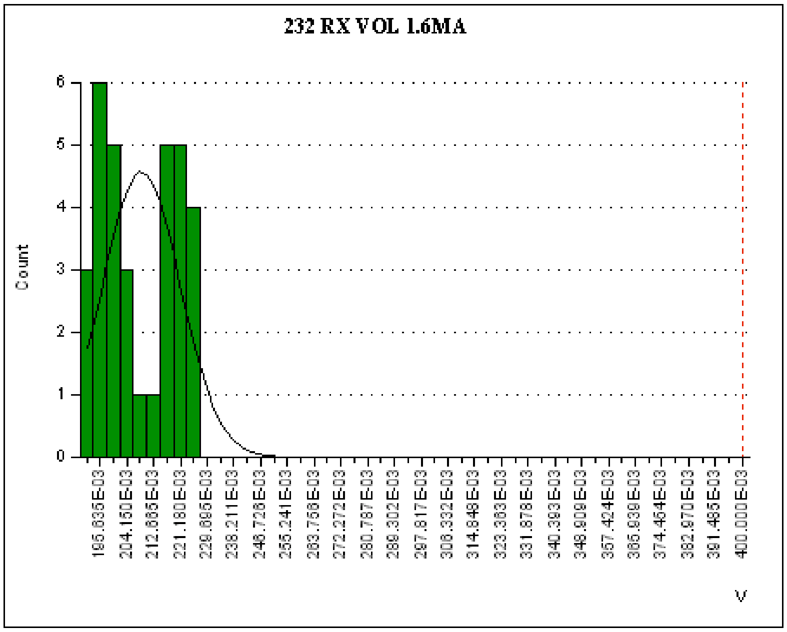
Min	181.177E-03	**Skew**	3.3071
Max	264.263E-03	**StatHigh**	N/A
Mean	194.795E-03	**StatLow**	N/A
StdDev	15.621E-03	**NWithinSpec**	30
25%	186.678E-03	**NOutsideSpec**	0
Mean+3*StdDev	241.658E-03	**90%**	209.983E-03
		Range	83.085E-03
Mean-3*StdDev	147.933E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.005, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	191.377E-03	**StatLow**	N/A
Max	227.462E-03	**NWithinSpec**	33
Mean	208.394E-03	**NOutsideSpec**	0
StdDev	12.228E-03	**90%**	225.631E-03
25%	196.635E-03	**Range**	36.085E-03
Mean+3*StdDev	245.076E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	171.711E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.1591		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

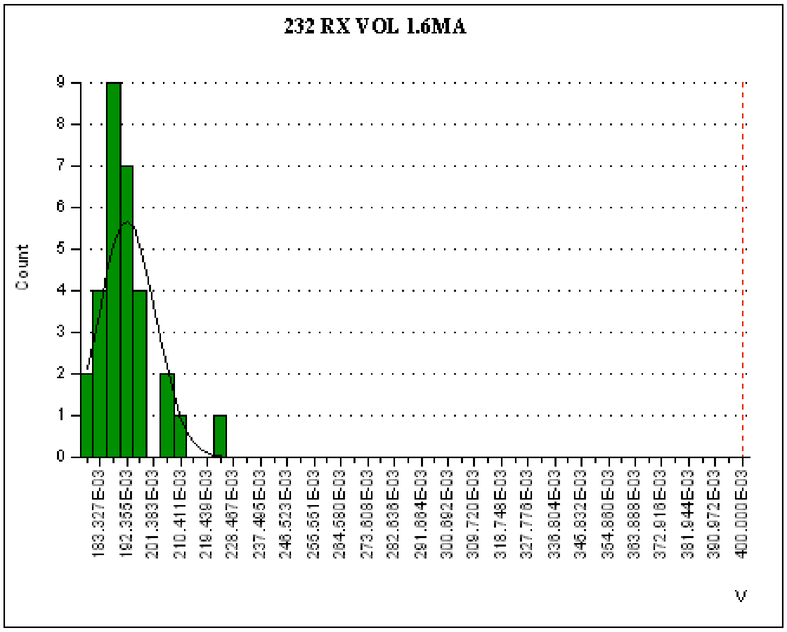
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.006, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

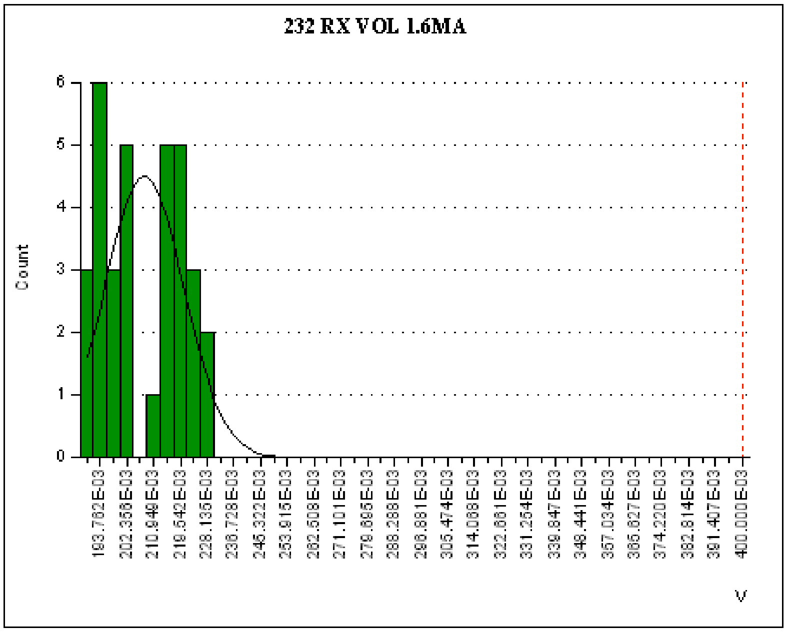
Min	178.813E-03	**Skew**	1.6308
Max	224.562E-03	**StatHigh**	N/A
Mean	192.091E-03	**StatLow**	N/A
StdDev	9.519E-03	**NWithinSpec**	30
25%	186.323E-03	**NOutsideSpec**	0
Mean+3*StdDev	220.647E-03	**90%**	205.670E-03
		Range	45.749E-03
Mean-3*StdDev	163.535E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.006, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	189.466E-03	**StatLow**	N/A
Max	227.841E-03	**NWithinSpec**	33
Mean	207.542E-03	**NOutsideSpec**	0
StdDev	12.555E-03	**90%**	223.669E-03
25%	195.241E-03	**Range**	38.375E-03
Mean+3*StdDev	245.207E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	169.876E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.0759		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

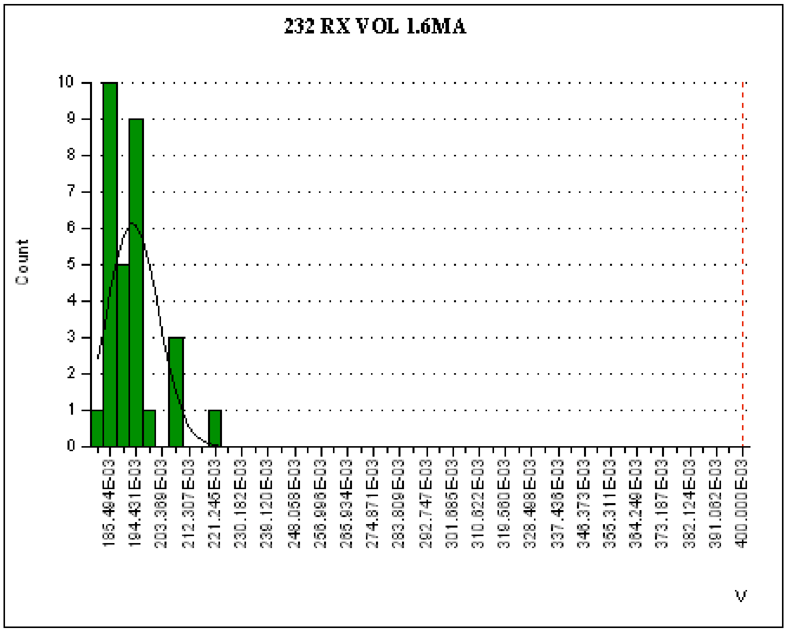
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.007, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

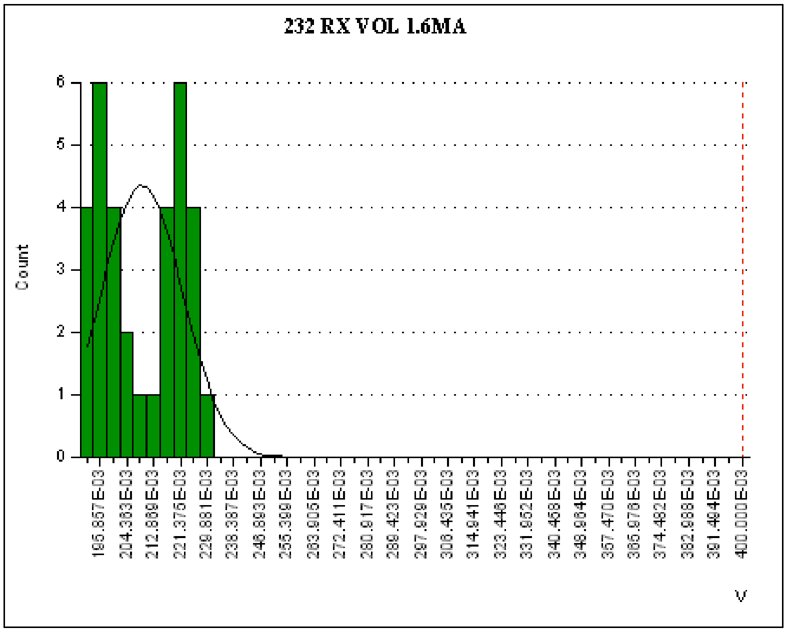
Min	181.025E-03	**Skew**	1.3043
Max	219.073E-03	**StatHigh**	N/A
Mean	192.824E-03	**StatLow**	N/A
StdDev	8.675E-03	**NWithinSpec**	30
25%	186.577E-03	**NOutsideSpec**	0
Mean+3*StdDev	218.848E-03	**90%**	206.889E-03
		Range	38.049E-03
Mean-3*StdDev	166.800E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.007, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	191.604E-03	**StatLow**	N/A
Max	229.841E-03	**NWithinSpec**	33
Mean	208.763E-03	**NOutsideSpec**	0
StdDev	12.806E-03	**90%**	224.772E-03
25%	195.866E-03	**Range**	38.236E-03
Mean+3*StdDev	247.181E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	170.346E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.0560		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

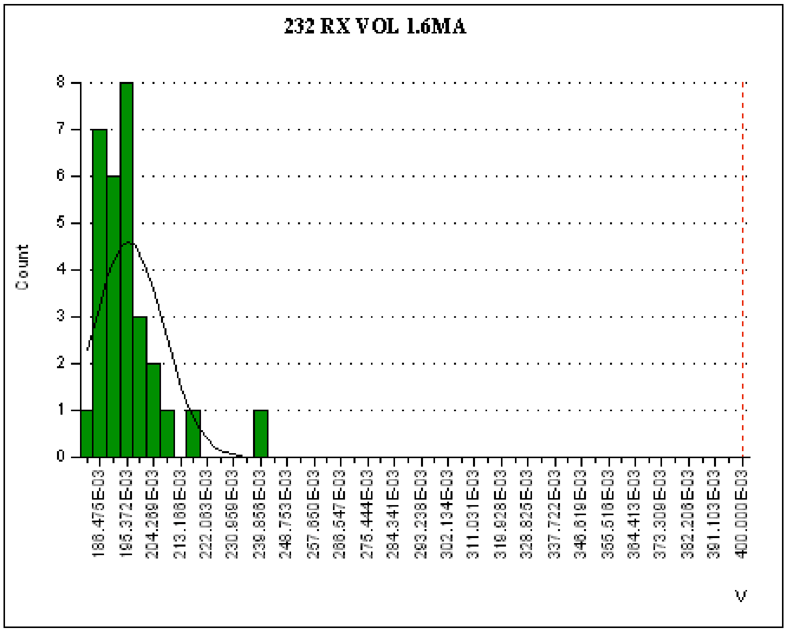
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.008, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

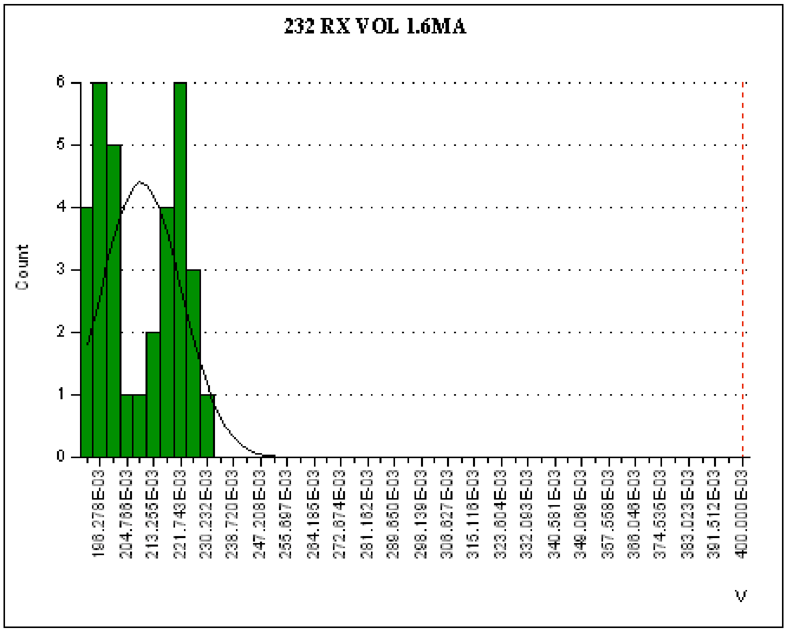
Min	182.027E-03	**Skew**	2.3383
Max	240.962E-03	**StatHigh**	N/A
Mean	195.639E-03	**StatLow**	N/A
StdDev	11.596E-03	**NWithinSpec**	30
25%	188.076E-03	**NOutsideSpec**	0
Mean+3*StdDev	230.428E-03	**90%**	207.742E-03
		Range	58.936E-03
Mean-3*StdDev	160.850E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.008, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	192.034E-03	**StatLow**	N/A
Max	230.080E-03	**NWithinSpec**	33
Mean	208.916E-03	**NOutsideSpec**	0
StdDev	12.669E-03	**90%**	225.391E-03
25%	197.557E-03	**Range**	38.047E-03
Mean+3*StdDev	246.924E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	170.908E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.0693		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

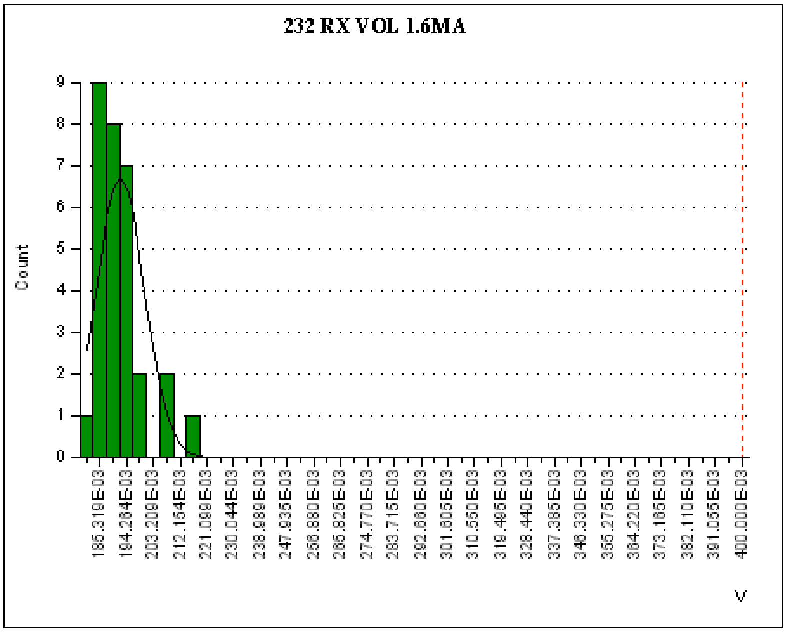
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.009, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

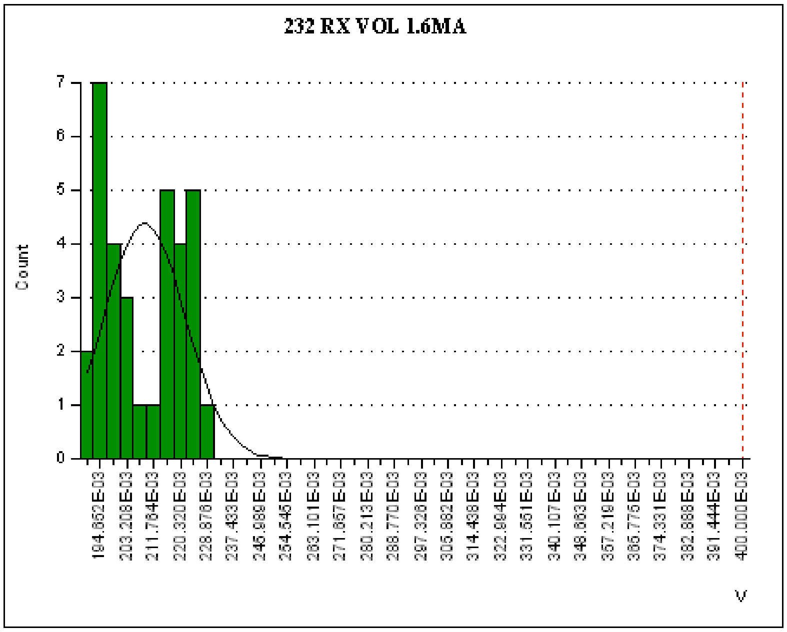
Min	180.847E-03	**Skew**	1.5676
Max	217.624E-03	**StatHigh**	N/A
Mean	191.841E-03	**StatLow**	N/A
StdDev	7.968E-03	**NWithinSpec**	30
25%	186.195E-03	**NOutsideSpec**	0
Mean+3*StdDev	215.745E-03	**90%**	203.193E-03
		Range	36.778E-03
Mean-3*StdDev	167.937E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.009, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	190.374E-03	**StatLow**	N/A
Max	230.106E-03	**NWithinSpec**	33
Mean	208.495E-03	**NOutsideSpec**	0
StdDev	12.863E-03	**90%**	225.606E-03
25%	195.953E-03	**Range**	39.732E-03
Mean+3*StdDev	247.083E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	169.907E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.0653		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

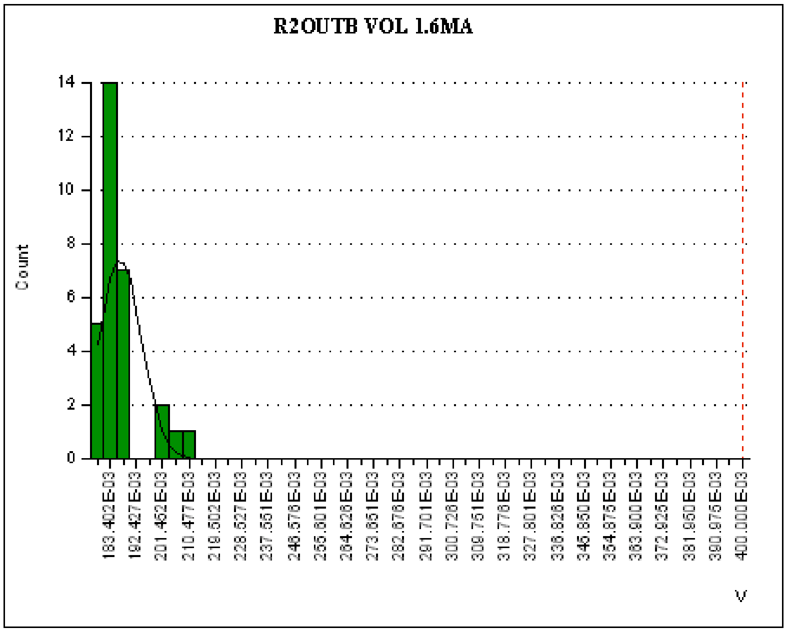
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.010, Test.Name=R2OUTB VOL 1.6MA



Statistics: (V)

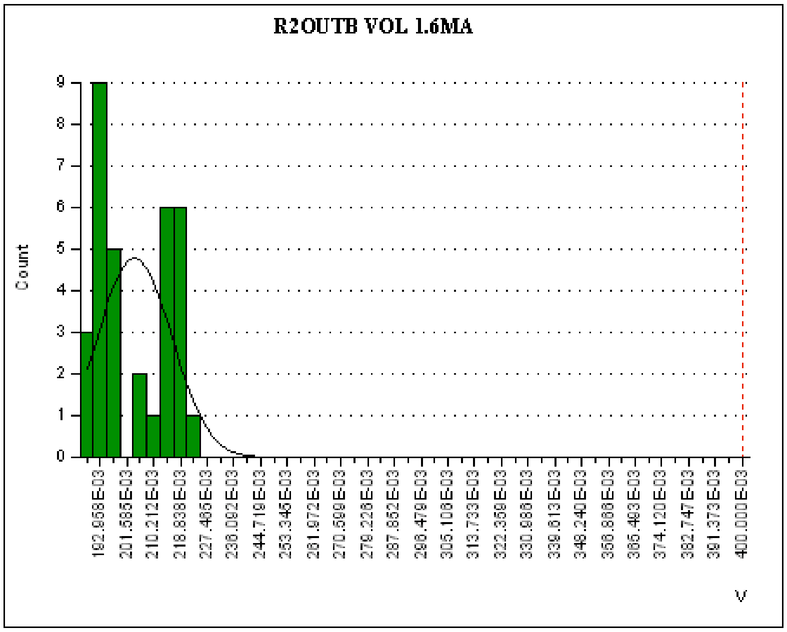
Min	178.889E-03	**Skew**	1.9001
Max	208.706E-03	**StatHigh**	N/A
Mean	186.531E-03	**StatLow**	N/A
StdDev	7.289E-03	**NWithinSpec**	30
25%	182.090E-03	**NOutsideSpec**	0
Mean+3*StdDev	208.397E-03	**90%**	199.477E-03
		Range	29.817E-03
Mean-3*StdDev	164.666E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.010, Test.Name=R2OUTB VOL 1.6MA



Statistics: (V)

Min	188.645E-03	**StatLow**	N/A
Max	221.080E-03	**NWithinSpec**	33
Mean	203.678E-03	**NOutsideSpec**	0
StdDev	11.857E-03	**90%**	218.613E-03
25%	192.425E-03	**Range**	32.435E+03
Mean+3*StdDev	239.249E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	168.108E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.1714		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

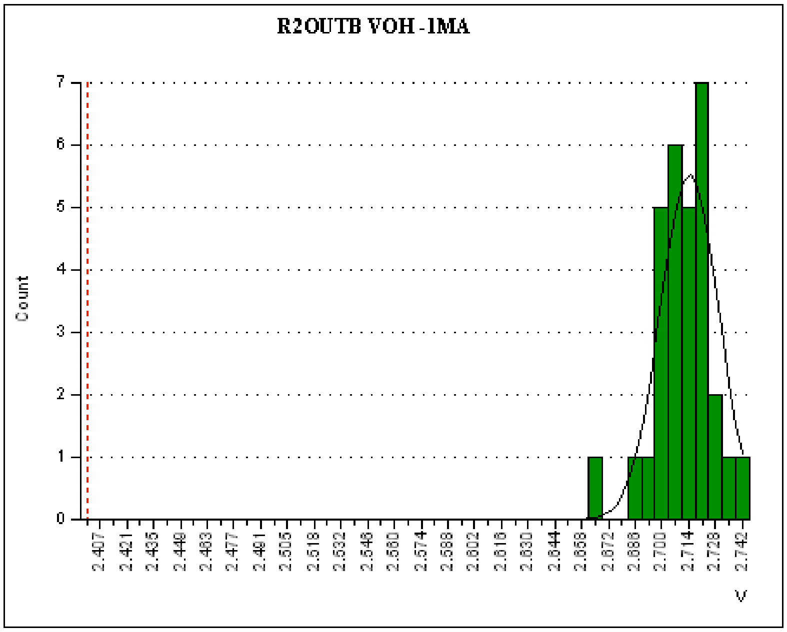
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=3.011, Test.Name=R2OUTB VOH -1MA



Statistics: (V)

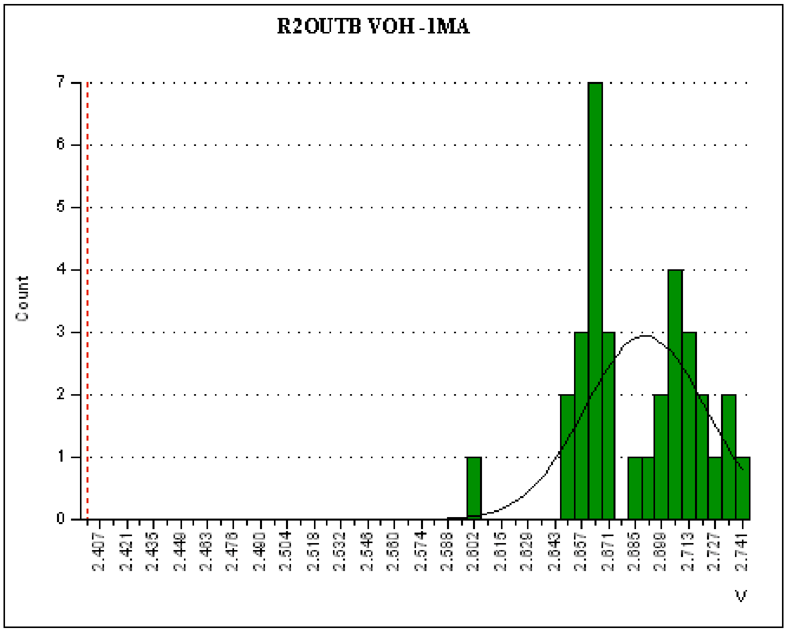
Min	2.663	**Skew**	-0.8159
Max	2.742	**StatHigh**	N/A
Mean	2.711	**StatLow**	N/A
StdDev	15.069E-03	**NWithinSpec**	30
25%	2.703	**NOutsideSpec**	0
Mean+3*StdDev	2.756	**90%**	2.727
		Range	78.205E-03
Mean-3*StdDev	2.665	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.011, Test.Name=R2OUTB VOH -1MA



Statistics: (V)

Min	2.605	**StatLow**	N/A
Max	2.741	**NWithinSpec**	33
Mean	2.687	**NOutsideSpec**	0
StdDev	31.016E-03	**90%**	2.726
25%	2.665	**Range**	135.765E-03
Mean+3*StdDev	2.780	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.594	**Cpl**	3.0828
		Cpu	N/A
Cpk	3.0828		
Skew	-0.2430		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

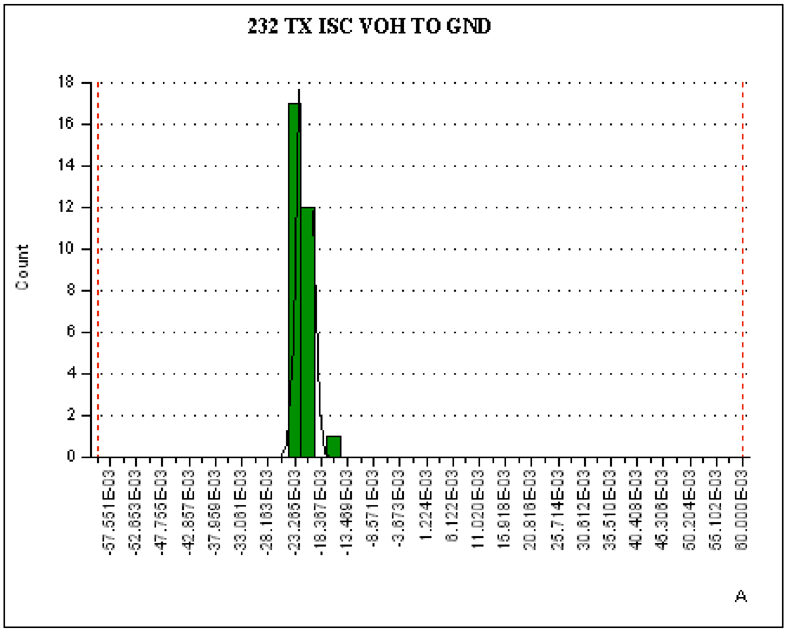
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=6.000, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

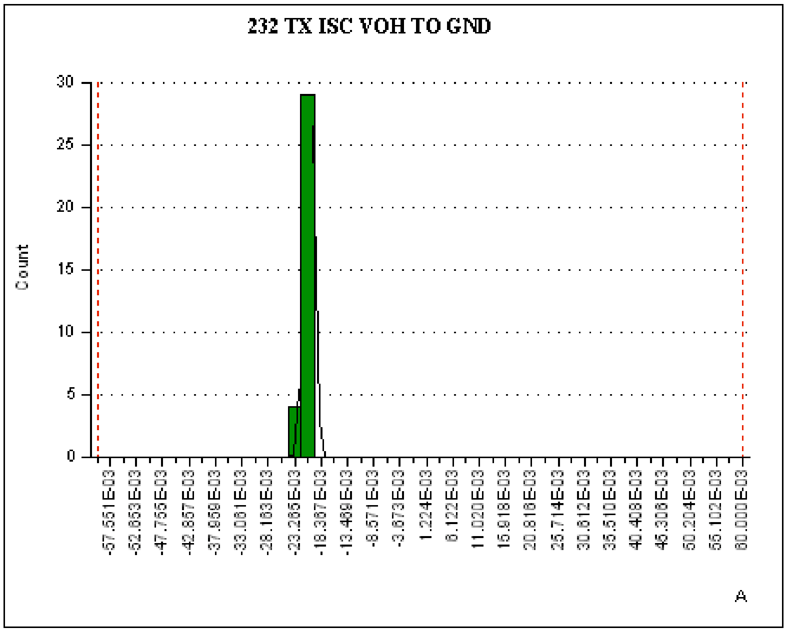
Min	-22.859E-03	**Skew**	3.8841
Max	-15.898E-03	**StatHigh**	N/A
Mean	-21.866E-03	**StatLow**	N/A
StdDev	1.256E-03	**NWithinSpec**	30
25%	-22.551E-03	**NOutsideSpec**	0
Mean+3*StdDev	-18.099E-03	**90%**	-21.235E-03
		Range	6.961E-03
Mean-3*StdDev	-25.634E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.000, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-22.340E-03	**StatLow**	N/A
Max	-19.956E-03	**NWithinSpec**	33
Mean	-21.119E-03	**NOutsideSpec**	0
StdDev	851.539E-06	**90%**	-20.156E-03
25%	-21.944E-03	**Range**	2.384E-03
Mean+3*StdDev	-18.565E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-23.674E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.0089		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

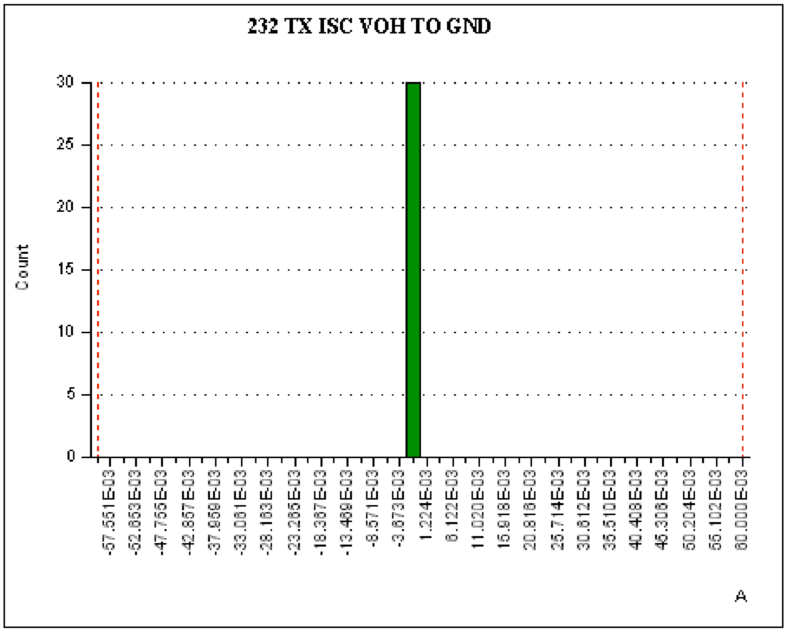
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=6.001, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

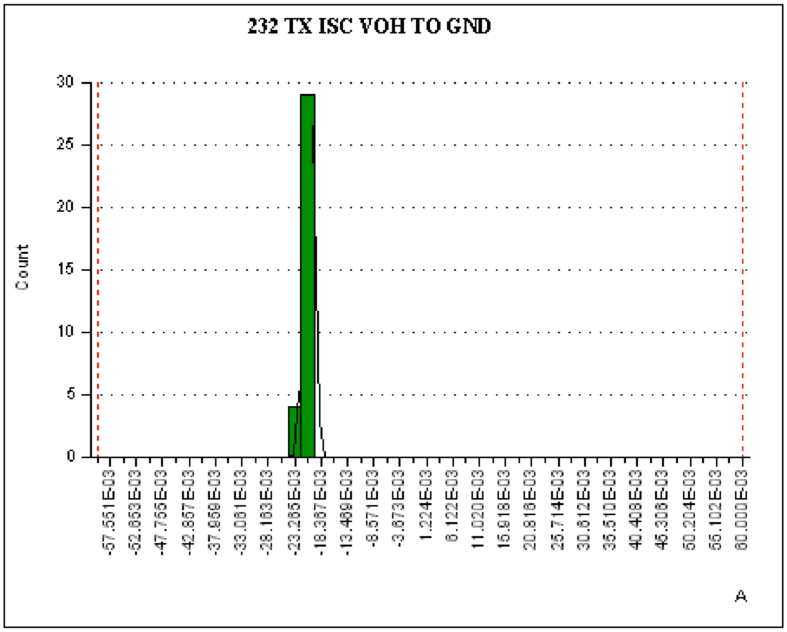
Min	-29.570E-06	**Skew**	-0.2014
Max	-2.194E-06	**StatHigh**	N/A
Mean	-14.123E-06	**StatLow**	N/A
StdDev	6.868E-06	**NWithinSpec**	30
25%	-19.166E-06	**NOutsideSpec**	0
Mean+3*StdDev	6.482E-06	**90%**	-5.470E-06
		Range	27.376E-06
Mean-3*StdDev	-34.728E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.001, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-22.318E-03	**StatLow**	N/A
Max	-19.988E-03	**NWithinSpec**	33
Mean	-21.121E-03	**NOutsideSpec**	0
StdDev	846.813E-06	**90%**	-20.165E-03
25%	-21.935E-03	**Range**	2.331E-03
Mean+3*StdDev	-18.580E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-23.661E-03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.0082		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

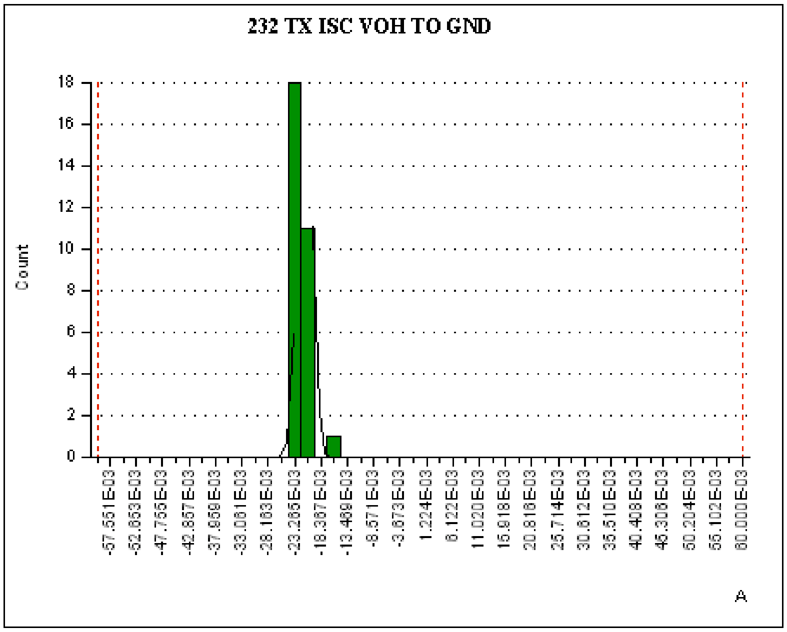
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=6.002, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

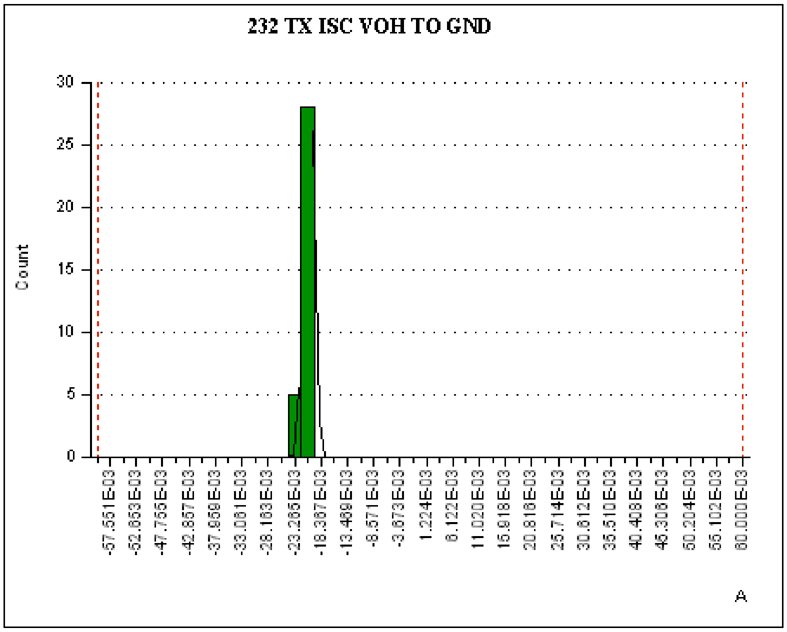
Min	-22.865E-03	**Skew**	4.0050
Max	-15.950E-03	**StatHigh**	N/A
Mean	-21.931E-03	**StatLow**	N/A
StdDev	1.247E-03	**NWithinSpec**	30
25%	-22.618E-03	**NOutsideSpec**	0
Mean+3*StdDev	-18.189E-03	**90%**	-21.307E-03
		Range	6.914E-03
Mean-3*StdDev	-25.673E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.002, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-22.323E-03	**StatLow**	N/A
Max	-19.977E-03	**NWithinSpec**	33
Mean	-21.132E-03	**NOutsideSpec**	0
StdDev	849.135E-06	**90%**	-20.156E-03
25%	-21.980E-03	**Range**	2.346E-03
Mean+3*StdDev	-18.585E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-23.680E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.0036		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

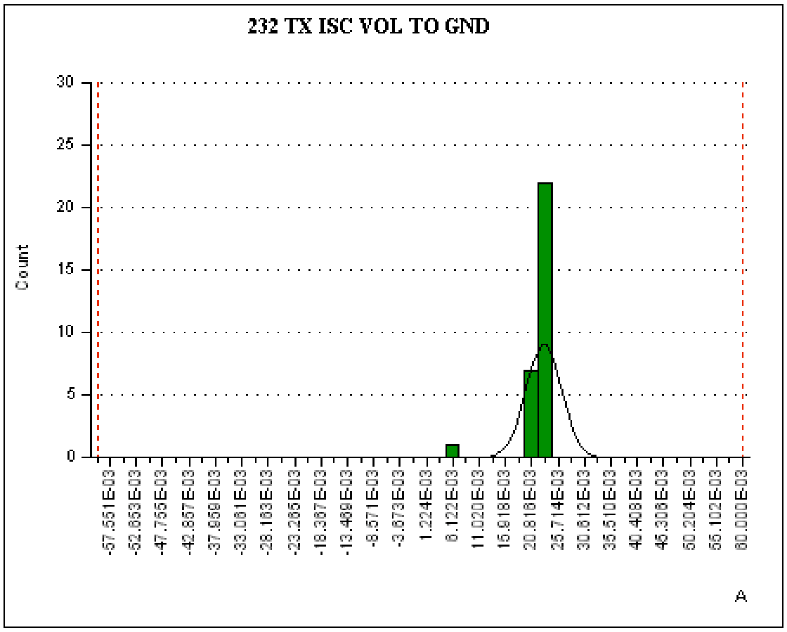
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=6.003, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

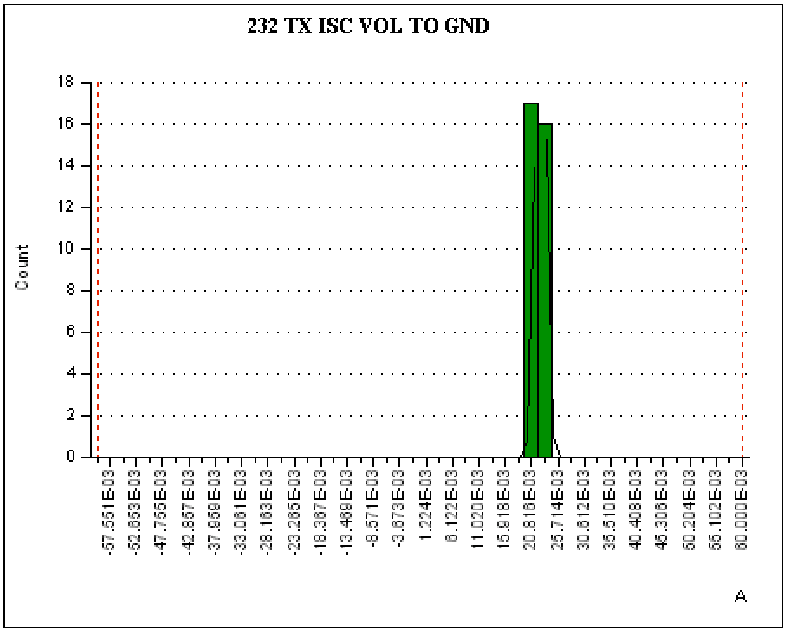
Min	5.519E-03	**Skew**	-5.1653
Max	23.588E-03	**StatHigh**	N/A
Mean	22.115E-03	**StatLow**	N/A
StdDev	3.192E-03	**NWithinSpec**	30
25%	22.025E-03	**NOutsideSpec**	0
Mean+3*StdDev	31.692E-03	**90%**	23.479E-03
		Range	18.069E-03
Mean-3*StdDev	12.538E-03	**NOutsideSpec**	0
Cpk	3.9559		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.003, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	20.453E-03	**StatLow**	N/A
Max	22.933E-03	**NWithinSpec**	33
Mean	21.631E-03	**NOutsideSpec**	0
StdDev	887.142E-06	**90%**	22.566E-03
25%	20.788E-03	**Range**	2.479E-03
Mean+3*StdDev	24.292E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	18.970E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.0490		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

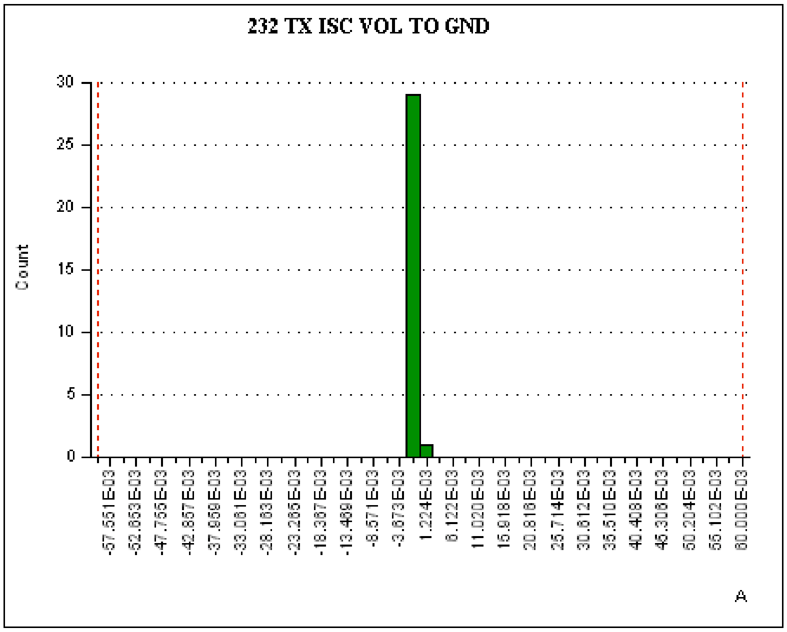
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=6.004, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

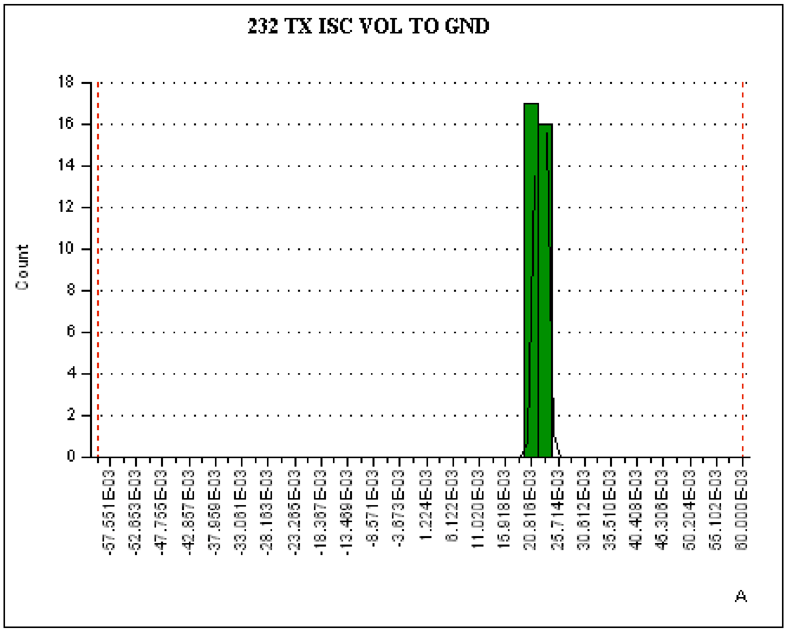
Min	-35.806E-06	**Skew**	0.5876
Max	5.754E-06	**StatHigh**	N/A
Mean	-18.901E-06	**StatLow**	N/A
StdDev	8.674E-06	**NWithinSpec**	30
25%	-23.334E-06	**NOutsideSpec**	0
Mean+3*StdDev	7.121E-06	**90%**	-6.809E-06
		Range	41.560E-06
Mean-3*StdDev	-44.923E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.004, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	20.463E-03	**StatLow**	N/A
Max	22.942E-03	**NWithinSpec**	33
Mean	21.647E-03	**NOutsideSpec**	0
StdDev	882.832E-06	**90%**	22.596E-03
25%	20.792E-03	**Range**	2.479E-03
Mean+3*StdDev	24.295E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	18.998E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.0534		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

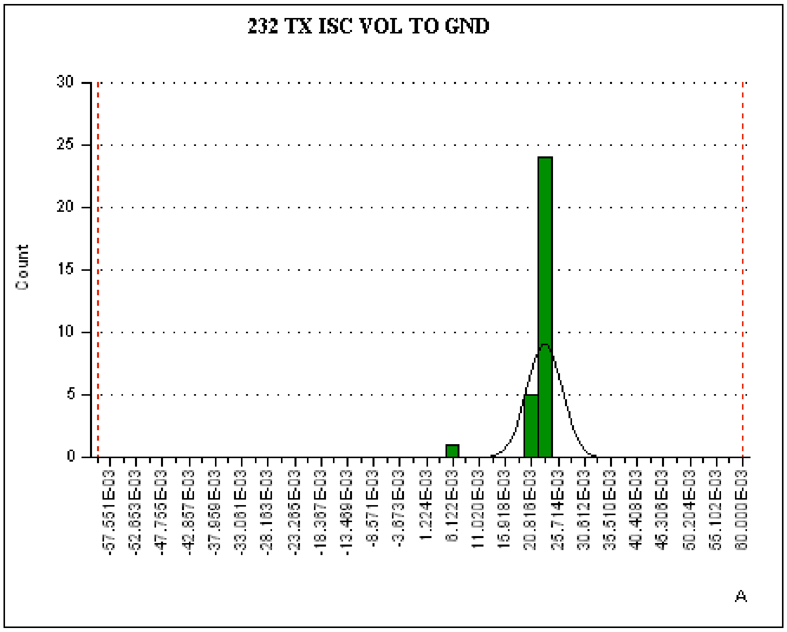
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=6.005, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

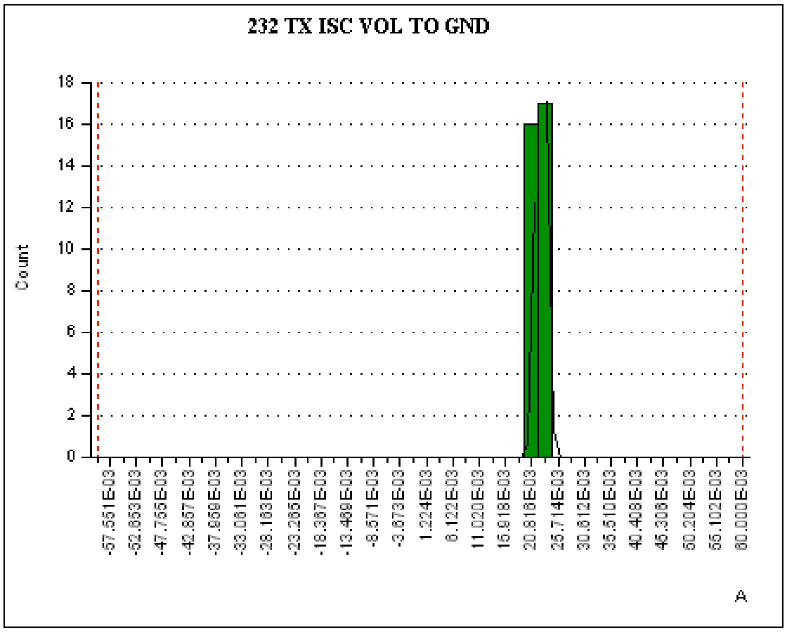
Min	5.539E-03	**Skew**	-5.1952
Max	23.646E-03	**StatHigh**	N/A
Mean	22.228E-03	**StatLow**	N/A
StdDev	3.204E-03	**NWithinSpec**	30
25%	22.076E-03	**NOutsideSpec**	0
Mean+3*StdDev	31.841E-03	**90%**	23.571E-03
		Range	18.107E-03
Mean-3*StdDev	12.615E-03	**NOutsideSpec**	0
Cpk	3.9291		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.005, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	20.495E-03	**StatLow**	N/A
Max	22.970E-03	**NWithinSpec**	33
Mean	21.709E-03	**NOutsideSpec**	0
StdDev	886.732E-06	**90%**	22.642E-03
25%	20.855E-03	**Range**	2.474E-03
Mean+3*StdDev	24.369E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	19.049E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.0618		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

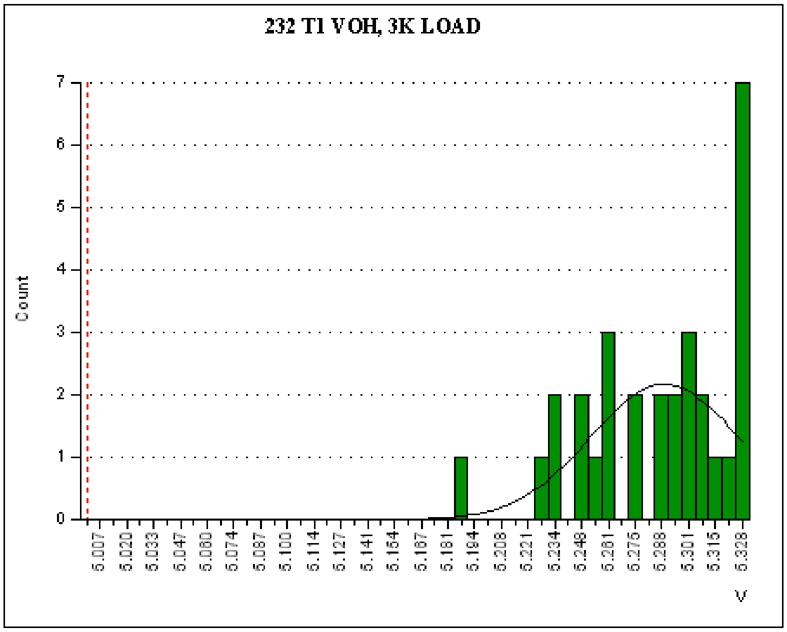
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=7.000, Test.Name=232 T1 VOH, 3K LOAD



Statistics: (V)

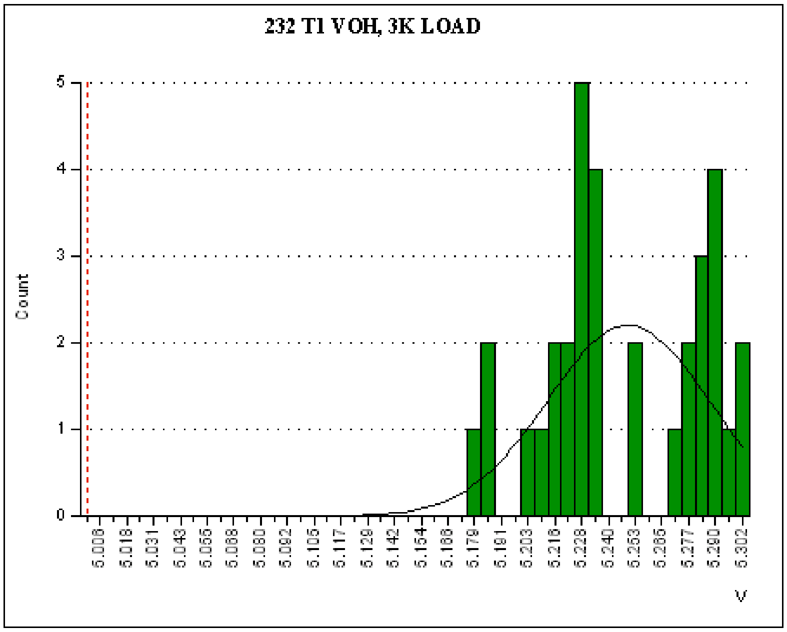
Min	5.189	**Skew**	-0.7132
Max	5.328	**StatHigh**	N/A
Mean	5.286	**StatLow**	N/A
StdDev	37.018E-03	**NWithinSpec**	30
25%	5.260	**NOutsideSpec**	0
Mean+3*StdDev	5.397	**90%**	5.327
		Range	139.419E-03
Mean-3*StdDev	5.175	**NOutsideSpec**	0
Cpk	2.5776		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.000, Test.Name=232 T1 VOH, 3K LOAD



Statistics: (V)

Min	5.176	**StatLow**	N/A
Max	5.302	**NWithinSpec**	33
Mean	5.247	**NOutsideSpec**	0
StdDev	36.826E-03	**90%**	5.292
25%	5.224	**Range**	125.979E-03
Mean+3*StdDev	5.357	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	5.136	**Cpl**	2.2329
Cpk	2.2329	**Cpu**	N/A
Skew	-0.0790		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

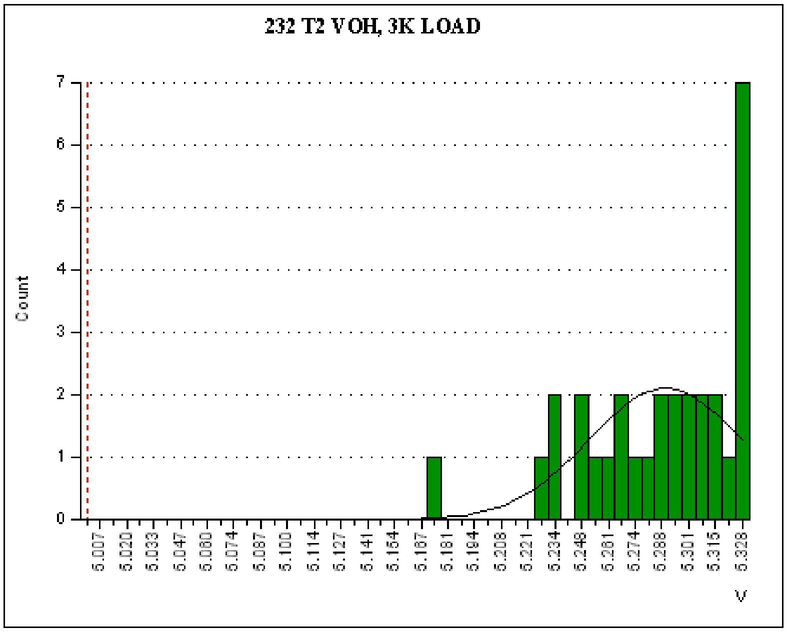
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=7.001, Test.Name=232 T2 VOH, 3K LOAD



Statistics: (V)

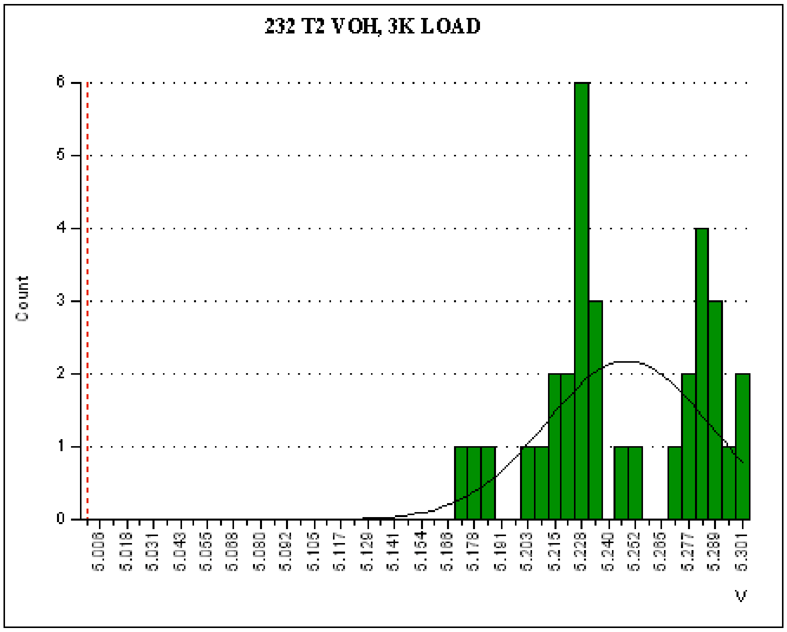
Min	5.175	**Skew**	-0.9669
Max	5.328	**StatHigh**	N/A
Mean	5.286	**StatLow**	N/A
StdDev	38.031E-03	**NWithinSpec**	30
25%	5.263	**NOutsideSpec**	0
Mean+3*StdDev	5.401	**90%**	5.327
		Range	153.177E-03
Mean-3*StdDev	5.172	**NOutsideSpec**	0
Cpk	2.5105		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.001, Test.Name=232 T2 VOH, 3K LOAD



Statistics: (V)

Min	5.173	**StatLow**	N/A
Max	5.301	**NWithinSpec**	33
Mean	5.246	**NOutsideSpec**	0
StdDev	37.218E-03	**90%**	5.290
25%	5.224	**Range**	128.723E-03
Mean+3*StdDev	5.357	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	5.134	**Cpl**	2.2002
Cpk	2.2002	**Cpu**	N/A
Skew	-0.1181		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

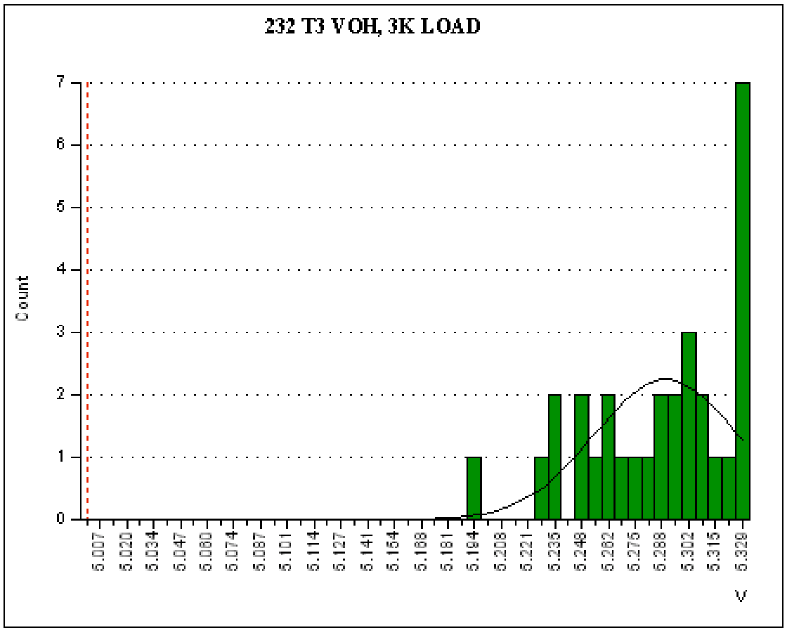
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=7.002, Test.Name=232 T3 VOH, 3K LOAD



Statistics: (V)

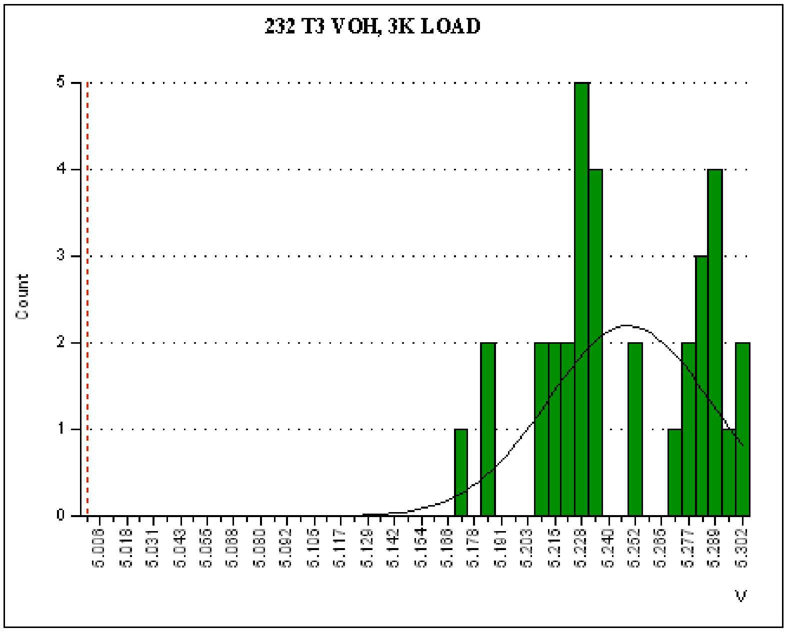
Min	5.198	**Skew**	-0.6717
Max	5.329	**StatHigh**	N/A
Mean	5.287	**StatLow**	N/A
StdDev	35.817E-03	**NWithinSpec**	30
25%	5.262	**NOutsideSpec**	0
Mean+3*StdDev	5.395	**90%**	5.327
		Range	130.954E-03
Mean-3*StdDev	5.180	**NOutsideSpec**	0
Cpk	2.6742		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.002, Test.Name=232 T3 VOH, 3K LOAD



Statistics: (V)

Min	5.175	**StatLow**	N/A
Max	5.302	**NWithinSpec**	33
Mean	5.247	**NOutsideSpec**	0
StdDev	36.890E-03	**90%**	5.291
25%	5.224	**Range**	126.702E-03
Mean+3*StdDev	5.357	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	5.136	**Cpl**	2.2282
Cpk	2.2282	**Cpu**	N/A
Skew	-0.0915		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

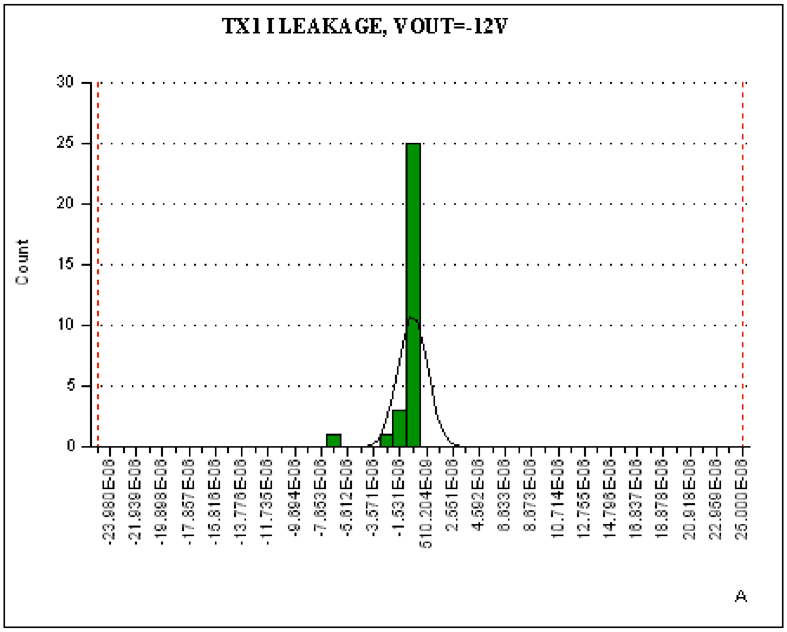
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=8.000, Test.Name=TX1 I LEAKAGE, VOUT=-12V



Statistics: (A)

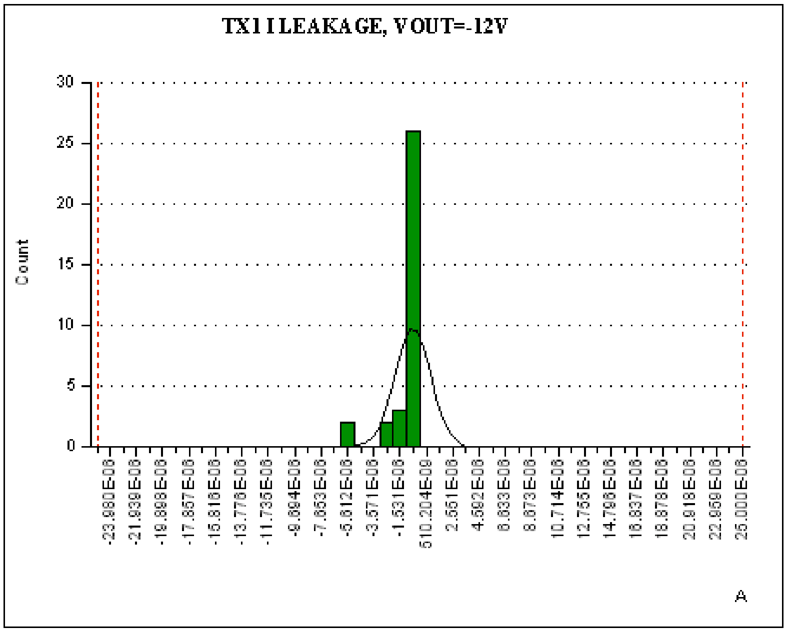
Min	-6.342E-06	**Skew**	-4.4341
Max	-186.895E-09	**StatHigh**	N/A
Mean	-827.799E-09	**StatLow**	N/A
StdDev	1.121E-06	**NWithinSpec**	30
25%	-766.362E-09	**NOutsideSpec**	0
Mean+3*StdDev	2.536E-06	**90%**	-317.515E-09
		Range	6.155E-06
Mean-3*StdDev	-4.191E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.000, Test.Name=TX1 I LEAKAGE, VOUT=-12V



Statistics: (A)

Min	-5.602E-06	**StatLow**	N/A
Max	-118.163E-09	**NWithinSpec**	33
Mean	-825.179E-09	**NOutsideSpec**	0
StdDev	1.363E-06	**90%**	-133.991E-09
25%	-691.694E-09	**Range**	5.484E-06
Mean+3*StdDev	3.262E-06	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-4.913E-06	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-2.7573		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

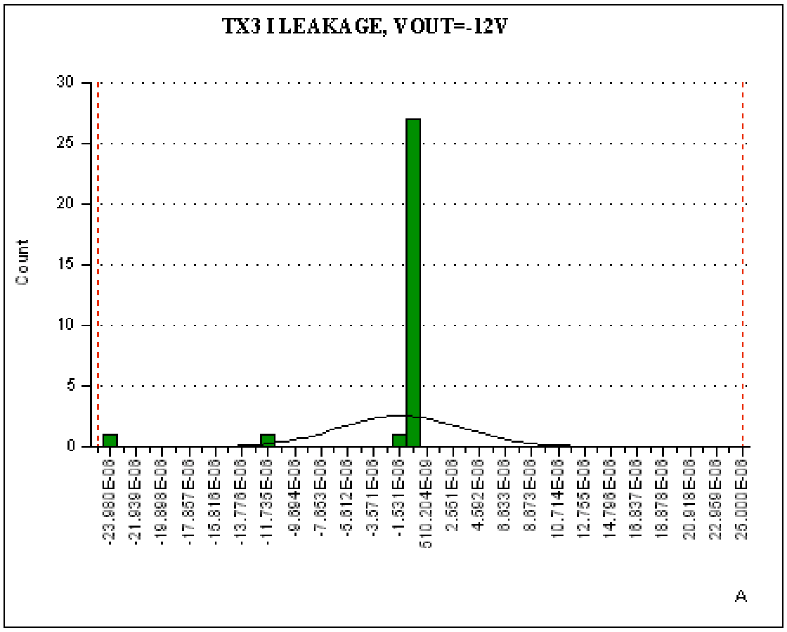
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=8.002, Test.Name=TX3 I LEAKAGE, VOUT=-12V



Statistics: (A)

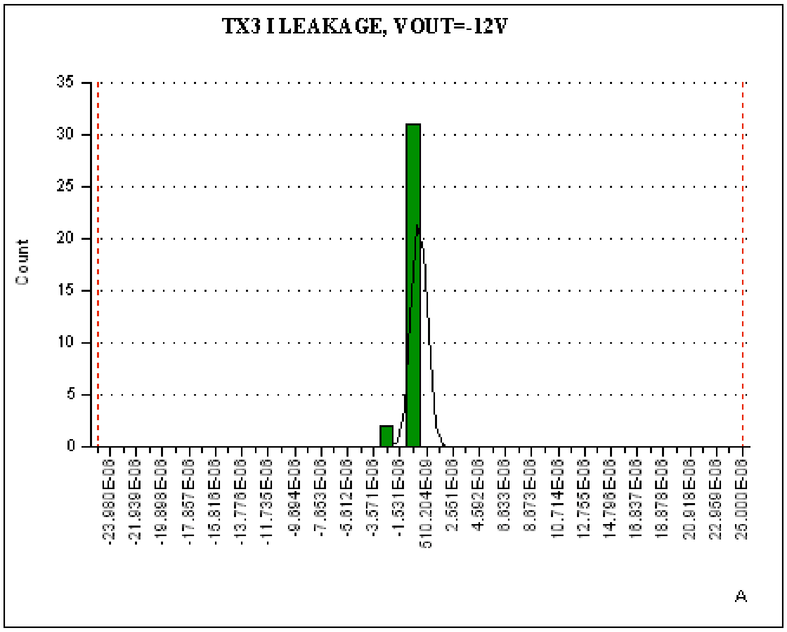
Min	-24.315E-06	**Skew**	-4.3350
Max	-228.183E-09	**StatHigh**	N/A
Mean	-1.648E-06	**StatLow**	N/A
StdDev	4.758E-06	**NWithinSpec**	30
25%	-575.179E-09	**NOutsideSpec**	0
Mean+3*StdDev	12.627E-06	**90%**	-307.301E-09
		Range	24.087E-06
Mean-3*StdDev	-15.923E-06	**NOutsideSpec**	0
Cpk	1.6359		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.002, Test.Name=TX3 I LEAKAGE, VOUT=-12V



Statistics: (A)

Min	-2.828E-06	**StatLow**	N/A
Max	-89.505E-09	**NWithinSpec**	33
Mean	-343.456E-09	**NOutsideSpec**	0
StdDev	610.877E-09	**90%**	-109.576E-09
25%	-207.526E-09	**Range**	2.738E-06
Mean+3*StdDev	1.489E-06	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-2.176E-06	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-3.6638		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

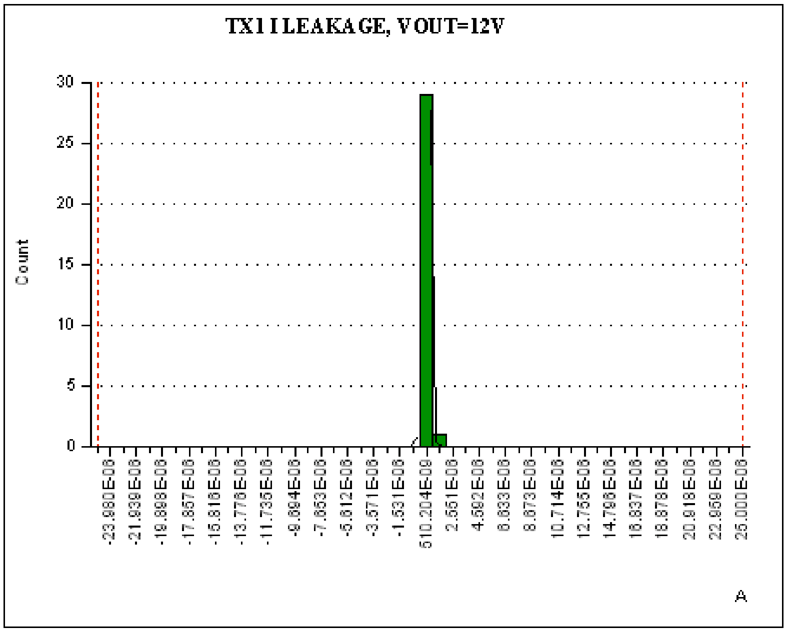
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=8.003, Test.Name=TX1 I LEAKAGE, VOUT=12V



Statistics: (A)

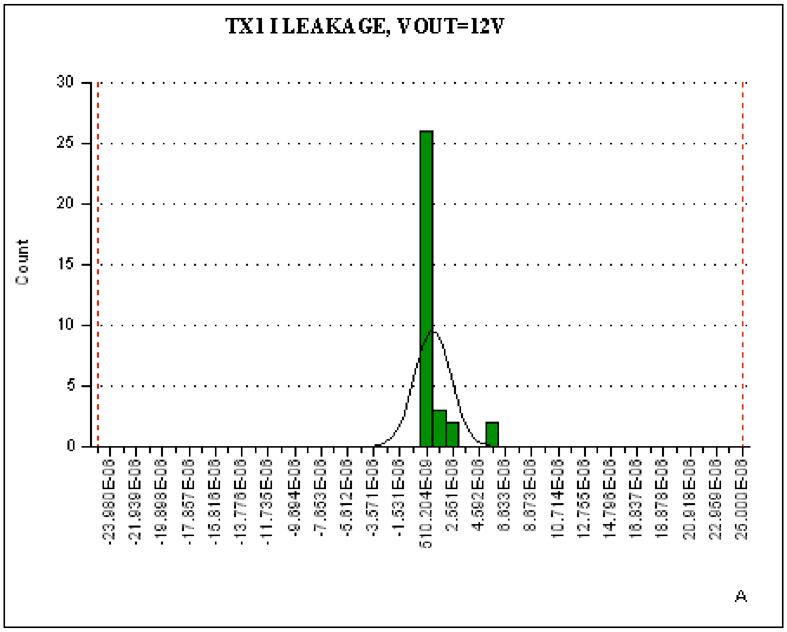
Min	32.274E-09	**Skew**	1.9438
Max	1.022E-06	**StatHigh**	N/A
Mean	233.517E-09	**StatLow**	N/A
StdDev	252.031E-09	**NWithinSpec**	30
25%	72.443E-09	**NOutsideSpec**	0
Mean+3*StdDev	989.611E-09	**90%**	560.572E-09
		Range	989.716E-09
Mean-3*StdDev	-522.577E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.003, Test.Name=TX1 I LEAKAGE, VOUT=12V



Statistics: (A)

Min	12.939E-09	**StatLow**	N/A
Max	5.530E-06	**NWithinSpec**	33
Mean	702.129E-09	**NOutsideSpec**	0
StdDev	1.383E-06	**90%**	2.073E-06
25%	55.514E-09	**Range**	5.518E-06
Mean+3*StdDev	4.852E-06	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-3.448E-06	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	2.7713		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

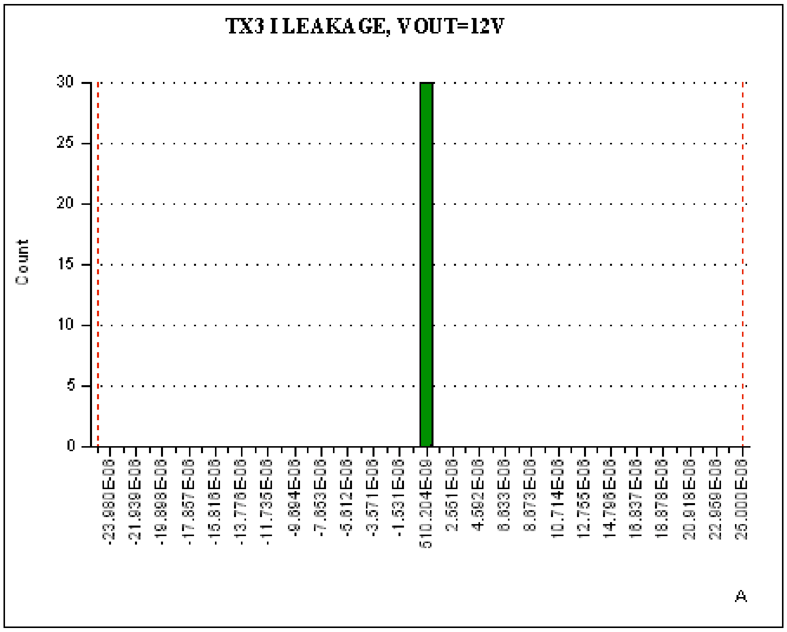
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=8.005, Test.Name=TX3 I LEAKAGE, VOUT=12V



Statistics: (A)

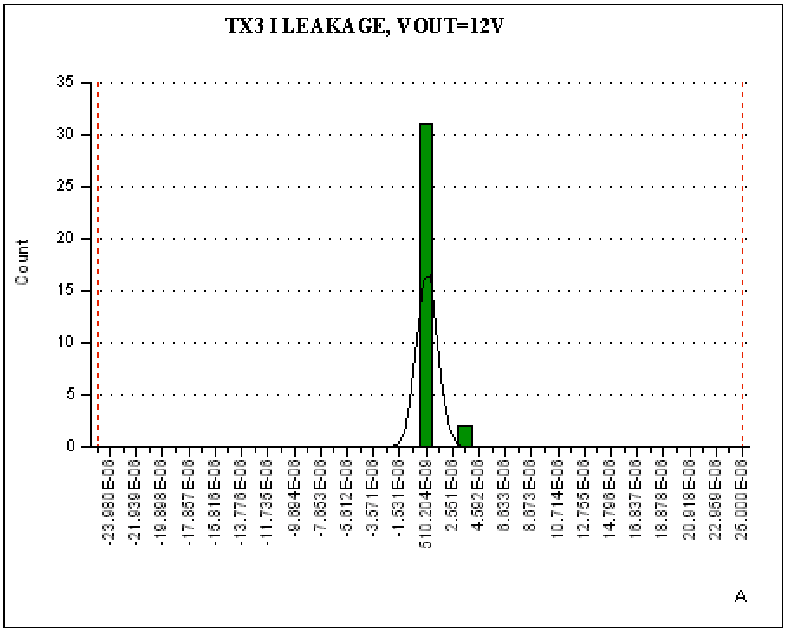
Min	20.109E-09	**Skew**	1.5833
Max	379.786E-09	**StatHigh**	N/A
Mean	119.192E-09	**StatLow**	N/A
StdDev	99.865E-09	**NWithinSpec**	30
25%	53.096E-09	**NOutsideSpec**	0
Mean+3*StdDev	418.787E-09	**90%**	289.257E-09
		Range	359.677E-09
Mean-3*StdDev	-180.403E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.005, Test.Name=TX3 I LEAKAGE, VOUT=12V



Statistics: (A)

Min	1.801E-09	**StatLow**	N/A
Max	3.384E-06	**NWithinSpec**	33
Mean	294.378E-09	**NOutsideSpec**	0
StdDev	786.674E-09	**90%**	571.736E-09
25%	31.936E-09	**Range**	3.382E-06
Mean+3*StdDev	2.654E-06	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-2.066E-06	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	3.6185		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

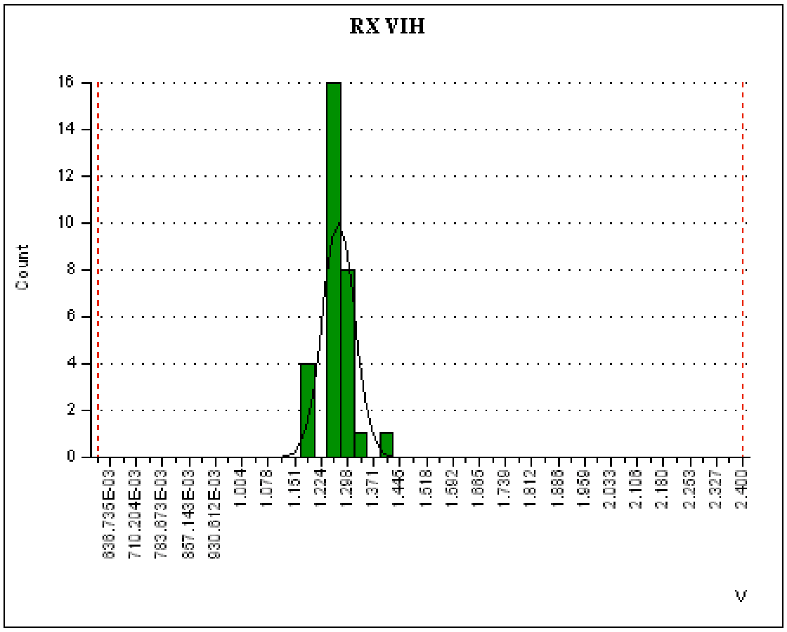
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.000, Test.Name=RX VIH



Statistics: (V)

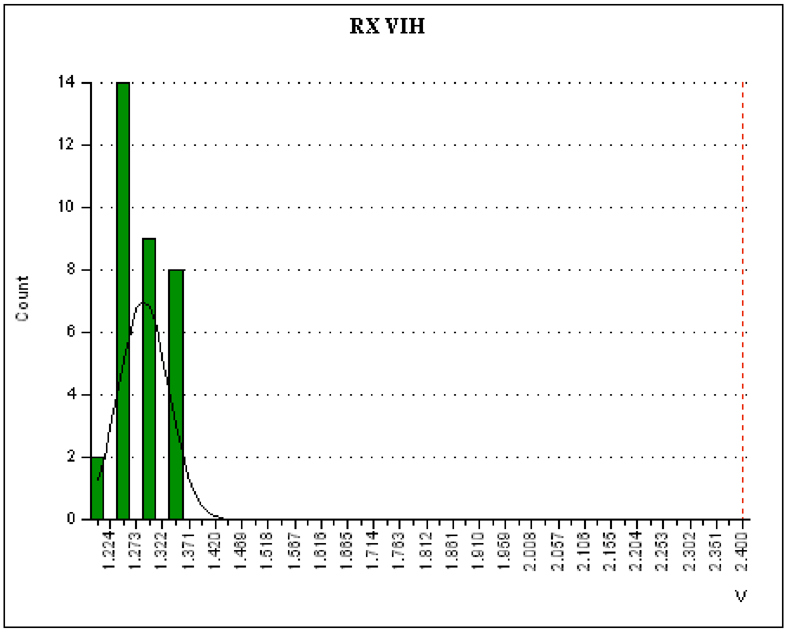
Min	1.200	**Skew**	0.9928
Max	1.400	**StatHigh**	N/A
Mean	1.265	**StatLow**	N/A
StdDev	43.845E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.397	**90%**	1.300
		Range	200.000E-03
Mean-3*StdDev	1.133	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.000, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.350	**NWithinSpec**	33
Mean	1.285	**NOutsideSpec**	0
StdDev	45.902E-03	**90%**	1.350
25%	1.250	**Range**	150.001E-03
Mean+3*StdDev	1.423	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.147	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.1477		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

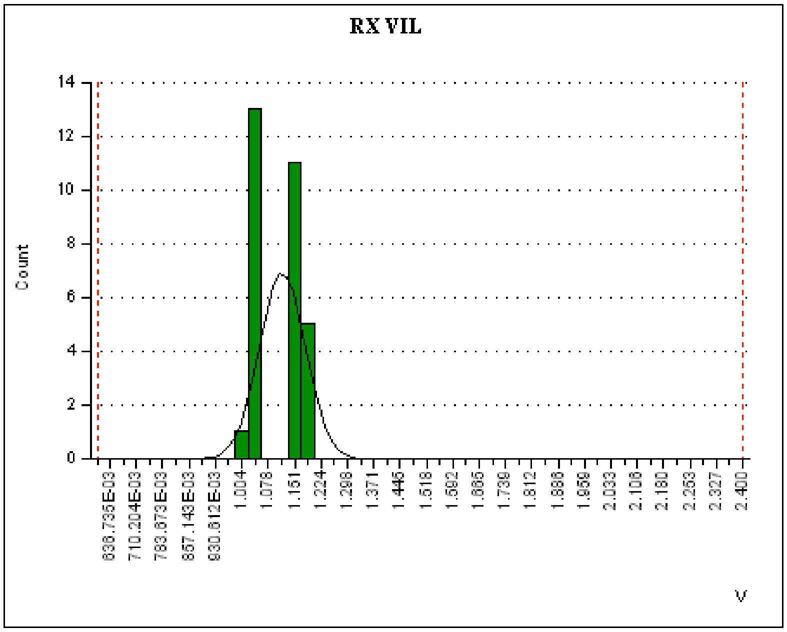
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.001, Test.Name=RX VIL



Statistics: (V)

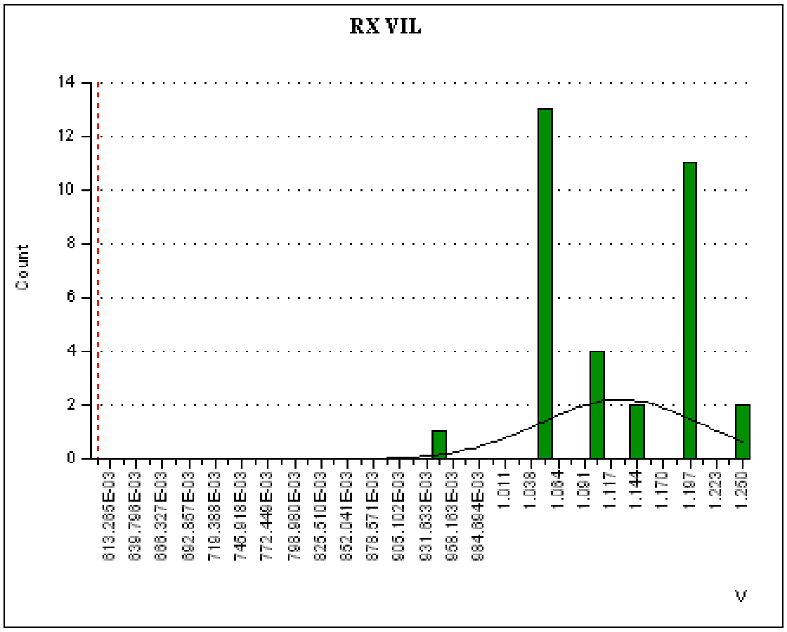
Min	1000.000E-03	**Skew**	0.0303
Max	1.200	**StatHigh**	N/A
Mean	1.110	**StatLow**	N/A
StdDev	63.518E-03	**NWithinSpec**	30
25%	1.050	**NOutsideSpec**	0
Mean+3*StdDev	1.301	**90%**	1.200
		Range	200.000E-03
Mean-3*StdDev	919.446E-03	**NOutsideSpec**	0
Cpk	2.6764		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.001, Test.Name=RX VIL



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.250	**NWithinSpec**	33
Mean	1.121	**NOutsideSpec**	0
StdDev	79.087E-03	**90%**	1.200
25%	1.050	**Range**	300.000E-03
Mean+3*StdDev	1.358	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	883.950E-03	**Cpl**	2.1968
		Cpu	N/A
Cpk	2.1968		
Skew	-0.0035		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

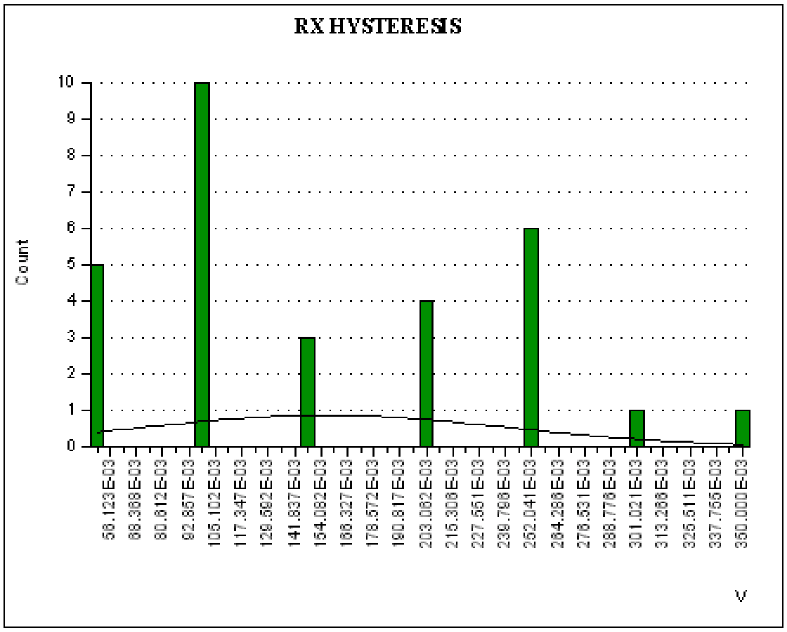
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.002, Test.Name=RX HYSTERESIS



Statistics: (V)

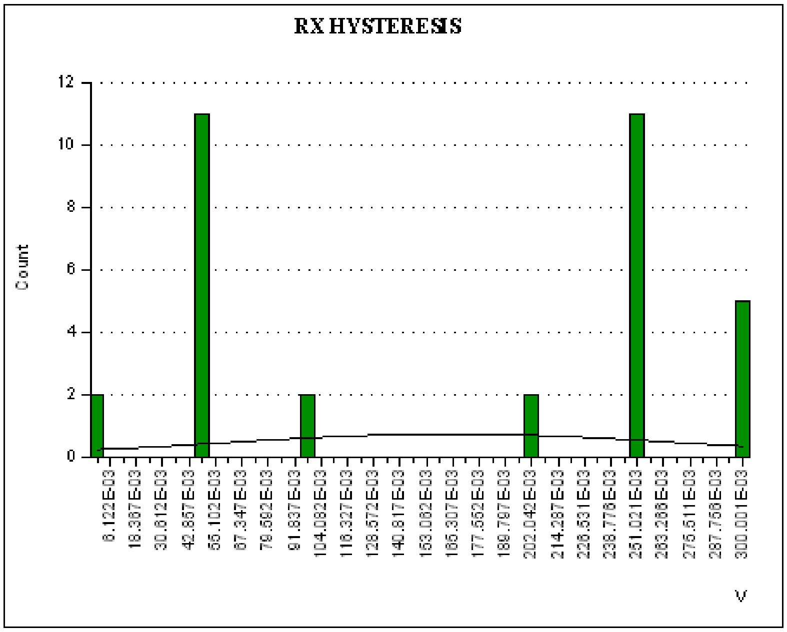
Min	50.000E-03	**Skew**	0.5229
Max	350.000E-03	**StatHigh**	N/A
Mean	155.001E-03	**StatLow**	N/A
StdDev	84.435E-03	**NWithinSpec**	N/A
25%	100.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	408.307E-03	**90%**	250.001E-03
		Range	300.000E-03
Mean-3*StdDev	-98.306E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.002, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	0	**StatLow**	N/A
Max	300.001E-03	**NWithinSpec**	N/A
Mean	163.637E-03	**NOutsideSpec**	N/A
StdDev	109.168E-03	**90%**	300.001E-03
25%	50.000E-03	**Range**	300.001E-03
Mean+3*StdDev	491.142E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-163.868E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.1422		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

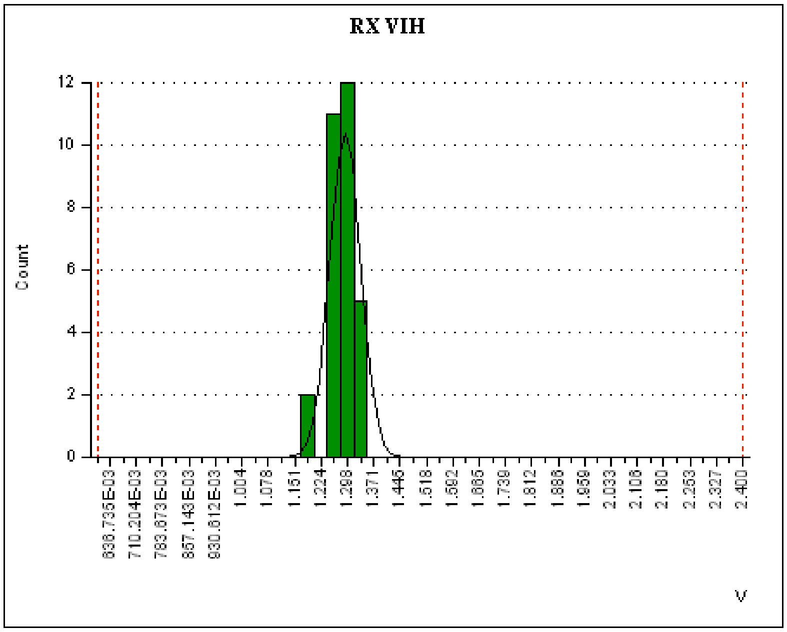
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.003, Test.Name=RX VIH



Statistics: (V)

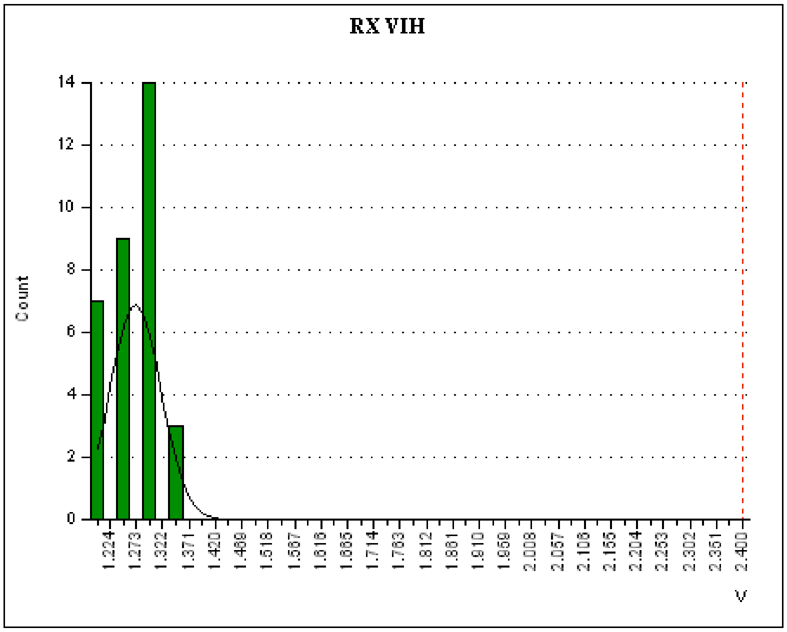
Min	1.200	**Skew**	-0.0136
Max	1.350	**StatHigh**	N/A
Mean	1.283	**StatLow**	N/A
StdDev	42.209E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.410	**90%**	1.350
		Range	150.001E-03
Mean-3*StdDev	1.157	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.003, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.350	**NWithinSpec**	33
Mean	1.270	**NOutsideSpec**	0
StdDev	46.670E-03	**90%**	1.300
25%	1.250	**Range**	150.001E-03
Mean+3*StdDev	1.410	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.130	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.1622		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

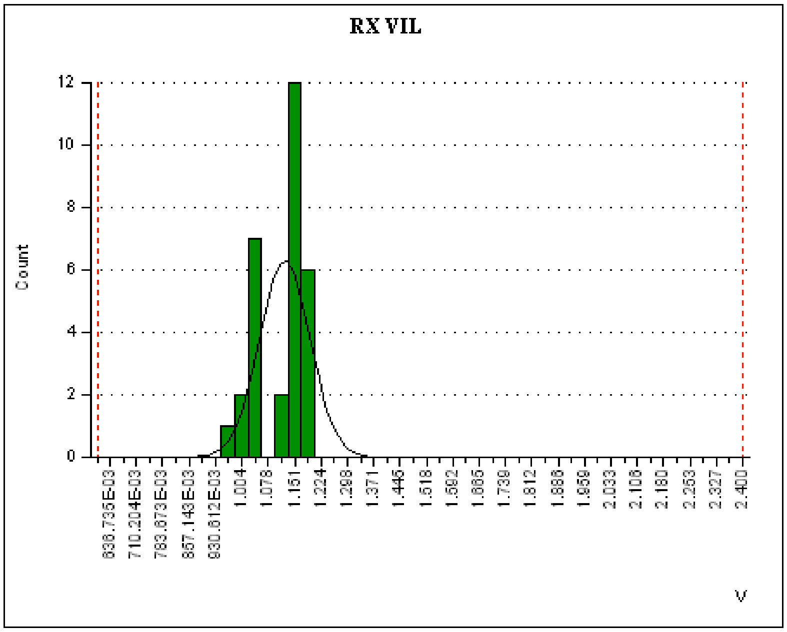
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.004, Test.Name=RX VIL



Statistics: (V)

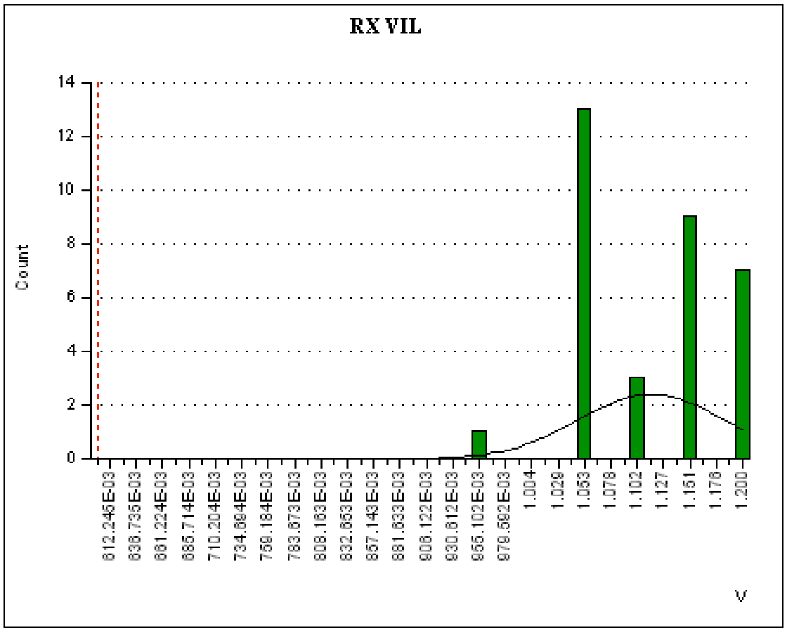
Min	950.000E-03	**Skew**	-0.6462
Max	1.200	**StatHigh**	N/A
Mean	1.117	**StatLow**	N/A
StdDev	69.893E-03	**NWithinSpec**	30
25%	1.050	**NOutsideSpec**	0
Mean+3*StdDev	1.326	**90%**	1.200
		Range	250.000E-03
Mean-3*StdDev	906.986E-03	**NOutsideSpec**	0
Cpk	2.4641		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.004, Test.Name=RX VIL



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.200	**NWithinSpec**	33
Mean	1.111	**NOutsideSpec**	0
StdDev	67.033E-03	**90%**	1.200
25%	1.050	**Range**	250.000E-03
Mean+3*StdDev	1.312	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	909.507E-03	**Cpl**	2.5391
Cpk	2.5391	**Cpu**	N/A
Skew	-0.1645		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

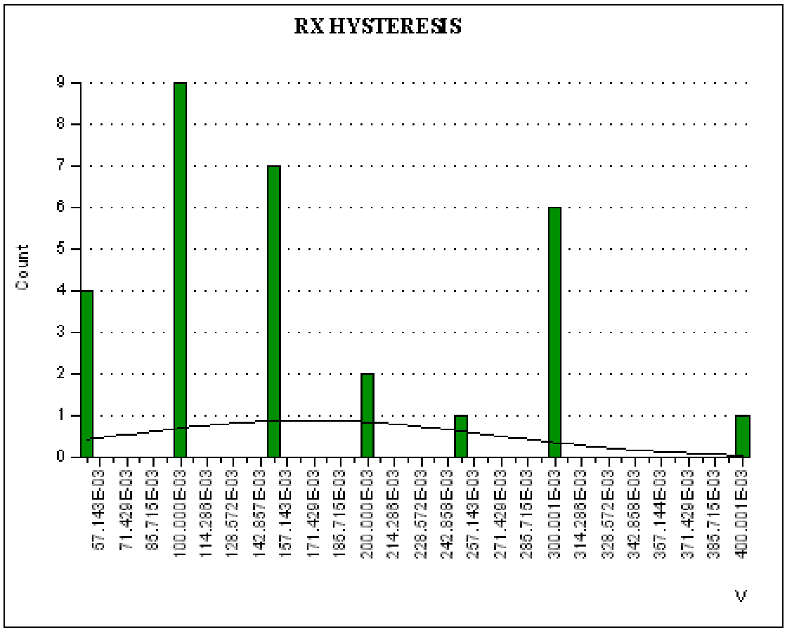
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.005, Test.Name=RX HYSTERESIS



Statistics: (V)

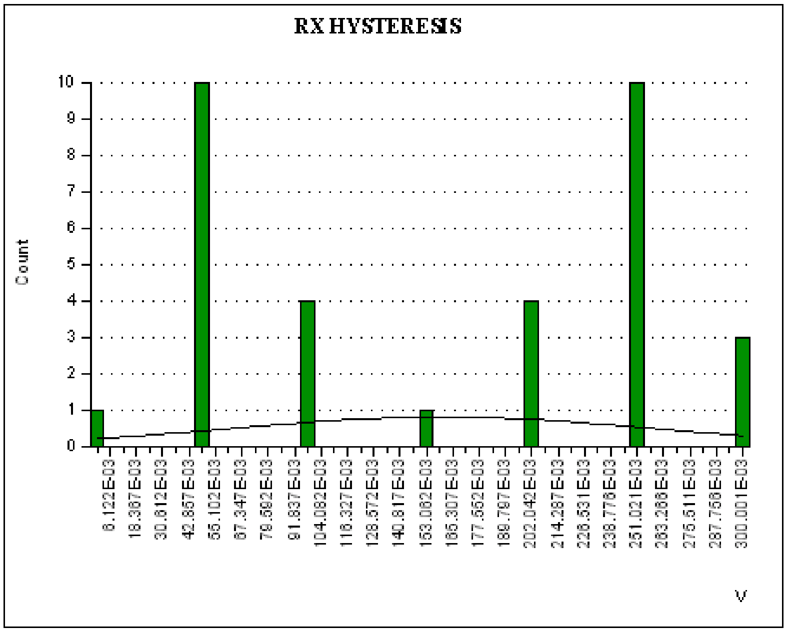
Min	50.000E-03	**Skew**	0.7763
Max	400.001E-03	**StatHigh**	N/A
Mean	166.667E-03	**StatLow**	N/A
StdDev	95.893E-03	**NWithinSpec**	N/A
25%	100.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	454.346E-03	**90%**	300.001E-03
		Range	350.001E-03
Mean-3*StdDev	-121.012E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.005, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	0	**StatLow**	N/A
Max	300.001E-03	**NWithinSpec**	N/A
Mean	159.091E-03	**NOutsideSpec**	N/A
StdDev	97.992E-03	**90%**	250.001E-03
25%	50.000E-03	**Range**	300.001E-03
Mean+3*StdDev	453.066E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-134.883E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0585		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

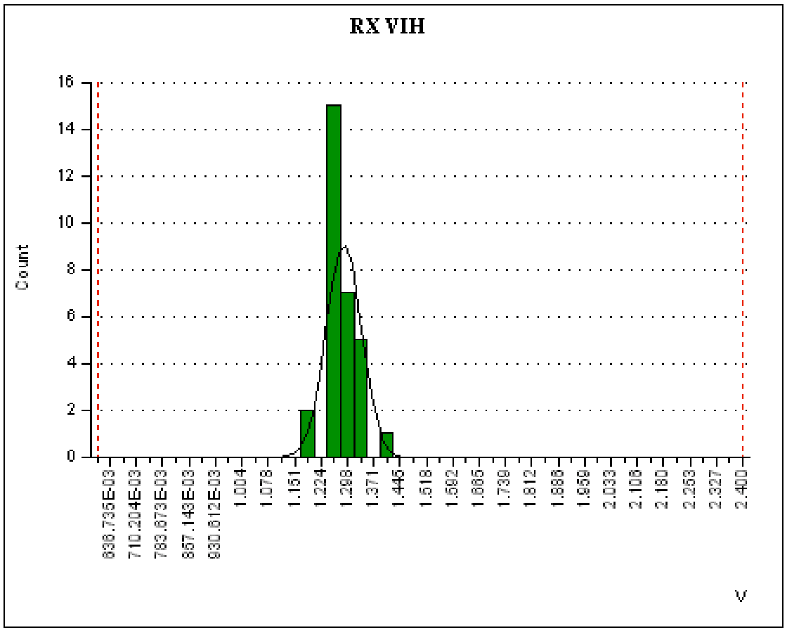
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.006, Test.Name=RX VIH



Statistics: (V)

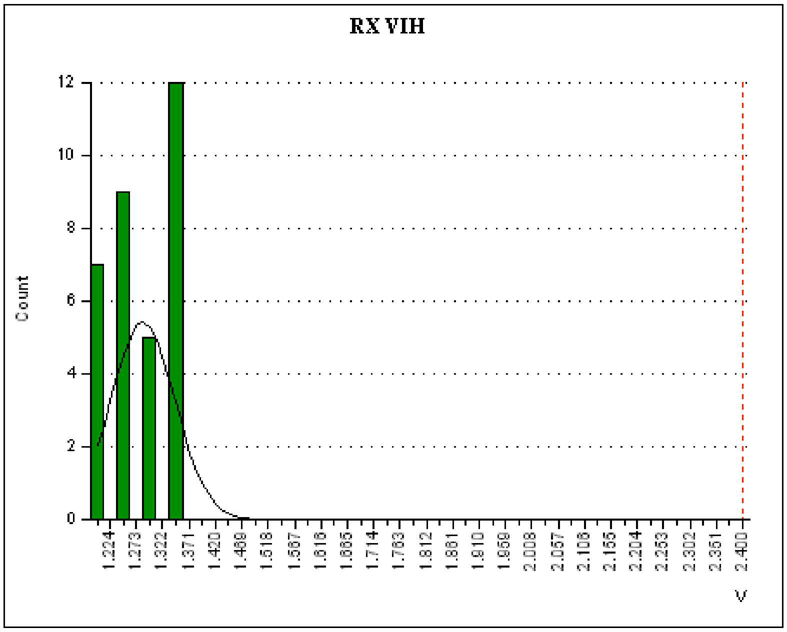
Min	1.200	**Skew**	0.6735
Max	1.400	**StatHigh**	N/A
Mean	1.280	**StatLow**	N/A
StdDev	48.424E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.425	**90%**	1.350
		Range	200.000E-03
Mean-3*StdDev	1.135	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.006, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.350	**NWithinSpec**	33
Mean	1.283	**NOutsideSpec**	0
StdDev	59.512E-03	**90%**	1.350
25%	1.250	**Range**	150.001E-03
Mean+3*StdDev	1.462	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.105	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.1271		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

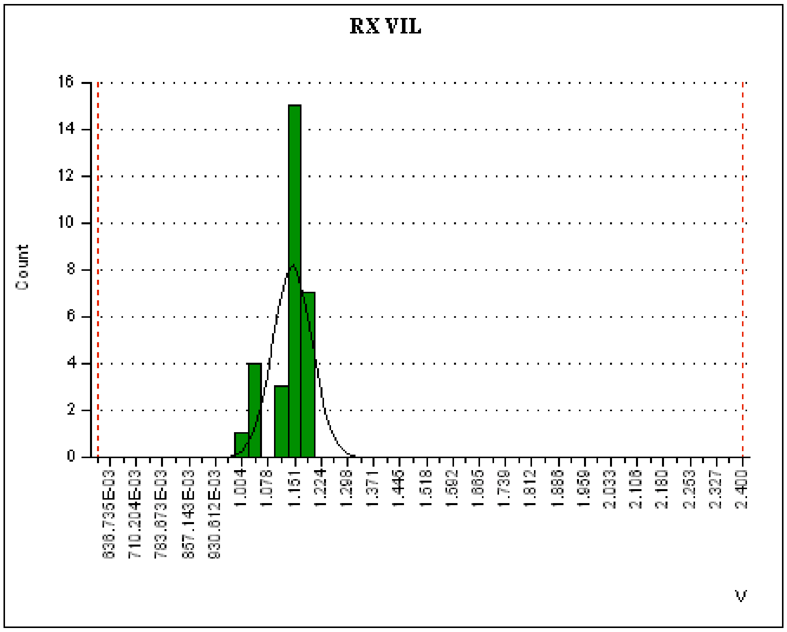
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.007, Test.Name=RX VIL



Statistics: (V)

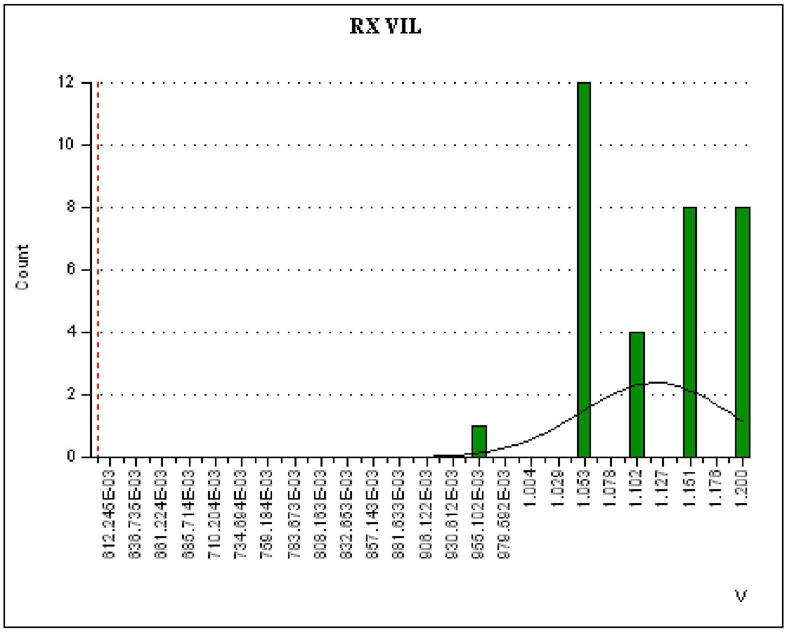
Min	1000.000E-03	**Skew**	-0.9359
Max	1.200	**StatHigh**	N/A
Mean	1.138	**StatLow**	N/A
StdDev	53.633E-03	**NWithinSpec**	30
25%	1.100	**NOutsideSpec**	0
Mean+3*StdDev	1.299	**90%**	1.200
		Range	200.000E-03
Mean-3*StdDev	977.435E-03	**NOutsideSpec**	0
Cpk	3.3458		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.007, Test.Name=RX VIL



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.200	**NWithinSpec**	33
Mean	1.114	**NOutsideSpec**	0
StdDev	67.631E-03	**90%**	1.200
25%	1.050	**Range**	250.000E-03
Mean+3*StdDev	1.317	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	910.744E-03	**Cpl**	2.5316
Cpk	2.5316	**Cpu**	N/A
Skew	-0.2093		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

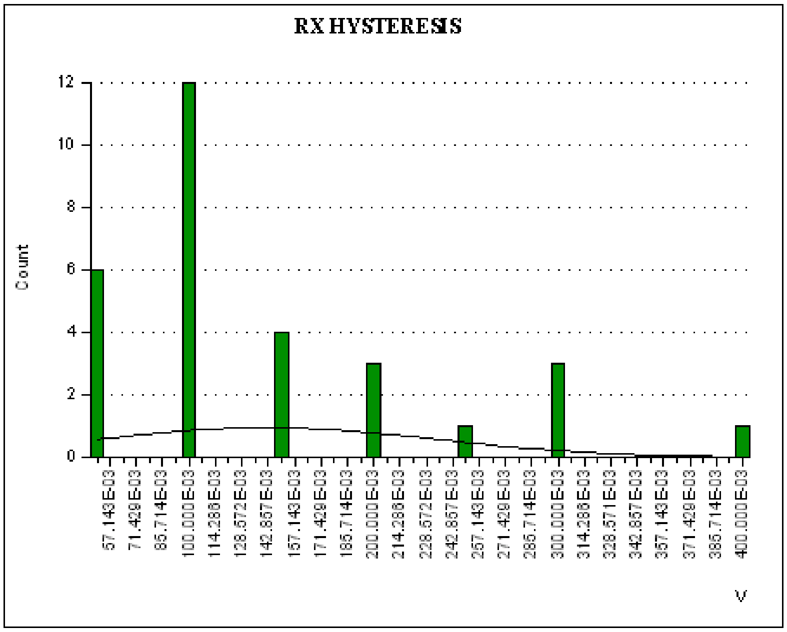
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.008, Test.Name=RX HYSTERESIS



Statistics: (V)

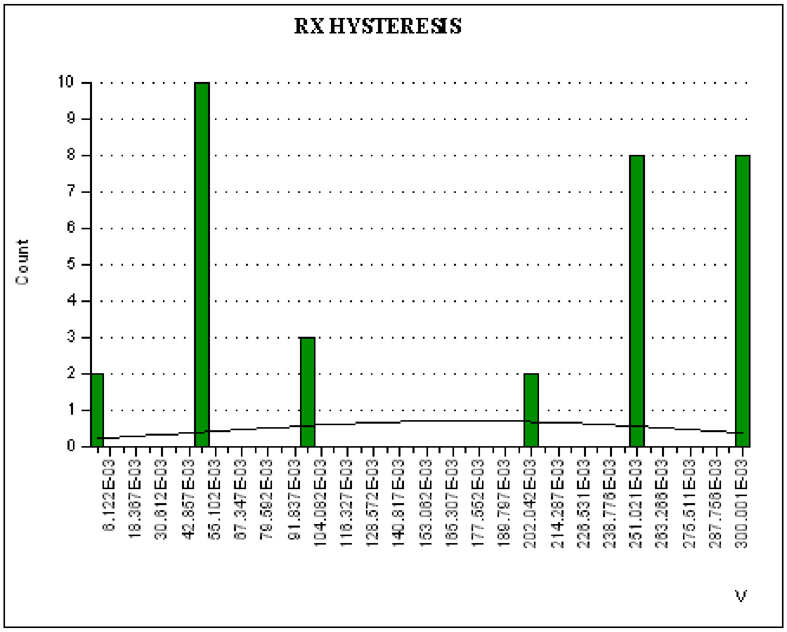
Min	50.000E-03	**Skew**	1.2895
Max	400.000E-03	**StatHigh**	N/A
Mean	141.667E-03	**StatLow**	N/A
StdDev	90.099E-03	**NWithinSpec**	N/A
25%	100.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	411.965E-03	**90%**	300.001E-03
		Range	350.000E-03
Mean-3*StdDev	-128.630E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	0	**StatLow**	N/A
Max	300.001E-03	**NWithinSpec**	N/A
Mean	169.698E-03	**NOutsideSpec**	N/A
StdDev	112.458E-03	**90%**	300.001E-03
25%	50.000E-03	**Range**	300.001E-03
Mean+3*StdDev	507.073E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-167.677E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.1413		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

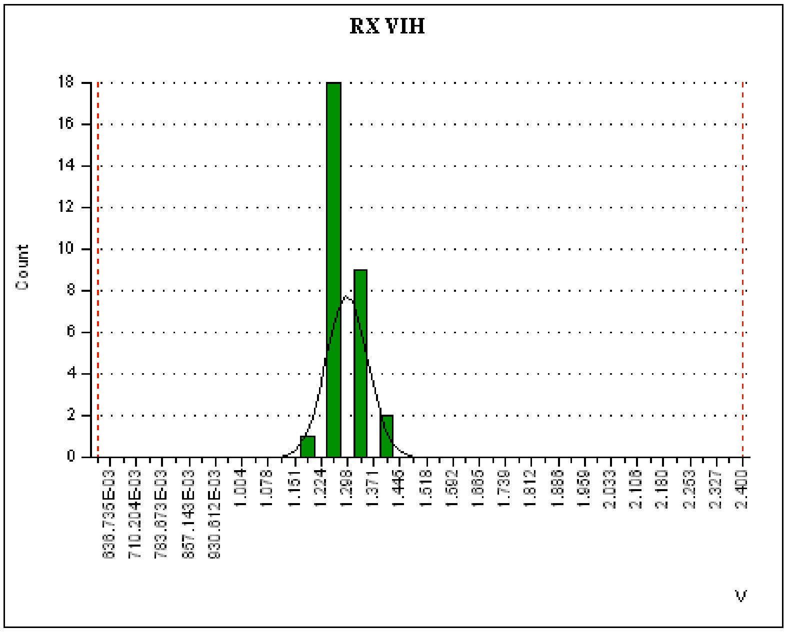
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.009, Test.Name=RX VIH



Statistics: (V)

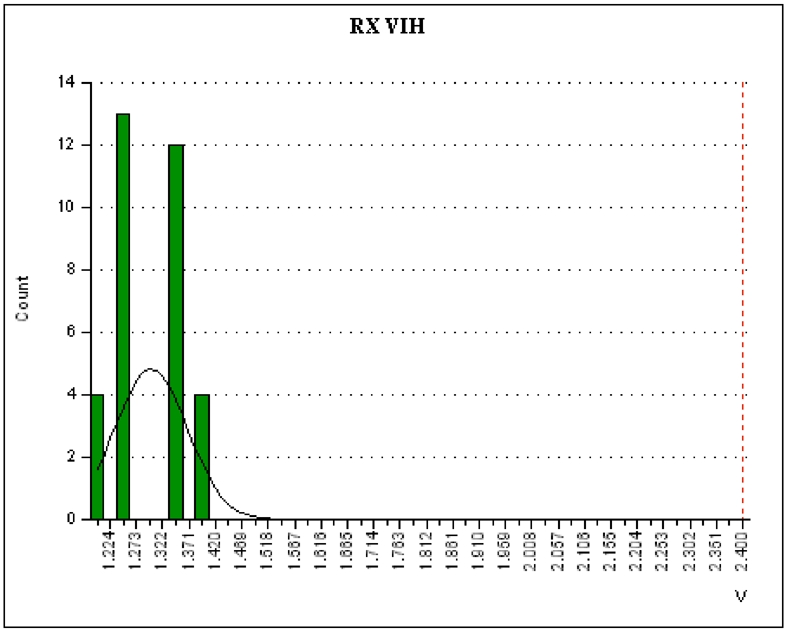
Min	1.200	**Skew**	0.6451
Max	1.400	**StatHigh**	N/A
Mean	1.288	**StatLow**	N/A
StdDev	56.756E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.459	**90%**	1.350
		Range	200.000E-03
Mean-3*StdDev	1.118	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.009, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.400	**NWithinSpec**	33
Mean	1.298	**NOutsideSpec**	0
StdDev	66.714E-03	**90%**	1.400
25%	1.250	**Range**	200.000E-03
Mean+3*StdDev	1.499	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.098	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.0585		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

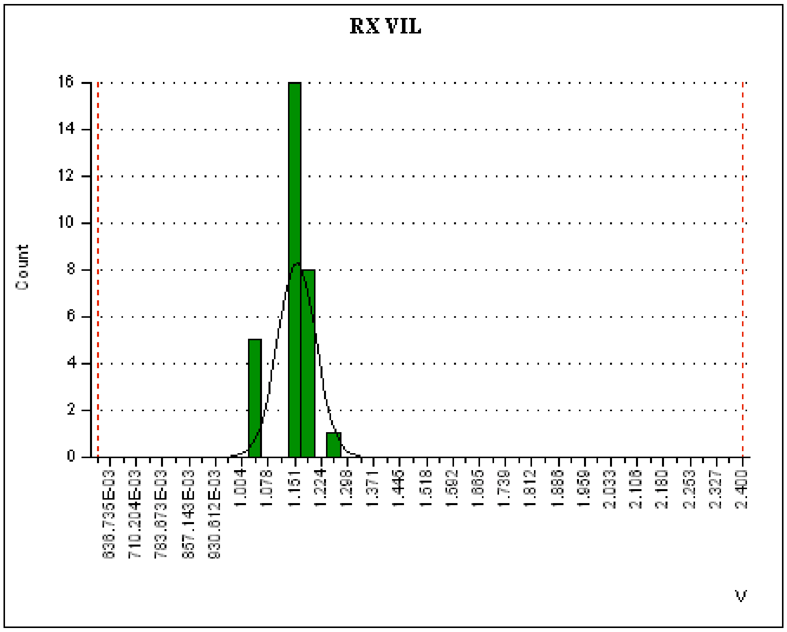
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.010, Test.Name=RX VIL



Statistics: (V)

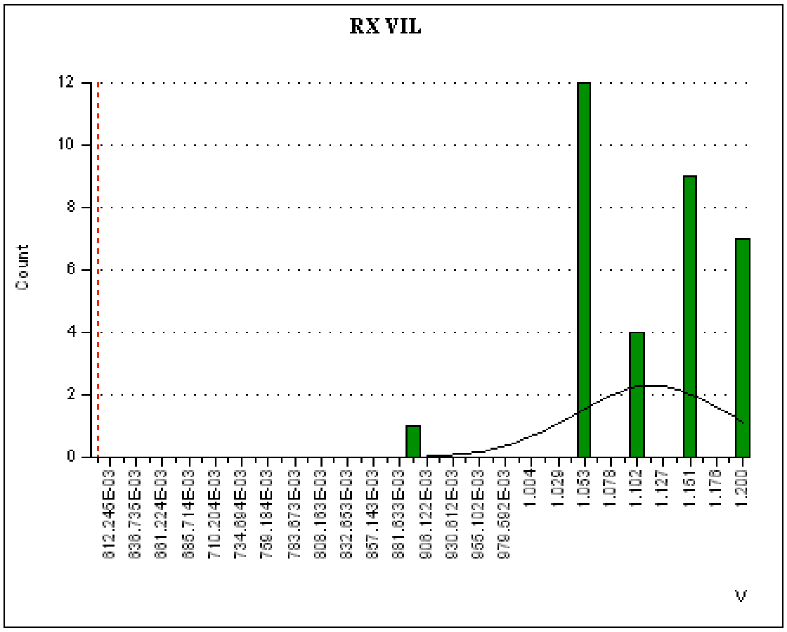
Min	1.050	**Skew**	-0.7650
Max	1.250	**StatHigh**	N/A
Mean	1.150	**StatLow**	N/A
StdDev	52.523E-03	**NWithinSpec**	30
25%	1.150	**NOutsideSpec**	0
Mean+3*StdDev	1.308	**90%**	1.200
		Range	200.001E-03
Mean-3*StdDev	992.431E-03	**NOutsideSpec**	0
Cpk	3.4905		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.010, Test.Name=RX VIL



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.200	**NWithinSpec**	33
Mean	1.111	**NOutsideSpec**	0
StdDev	70.443E-03	**90%**	1.200
25%	1.050	**Range**	300.000E-03
Mean+3*StdDev	1.322	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	899.278E-03	**Cpl**	2.4162
		Cpu	N/A
Cpk	2.4162		
Skew	-0.6154		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

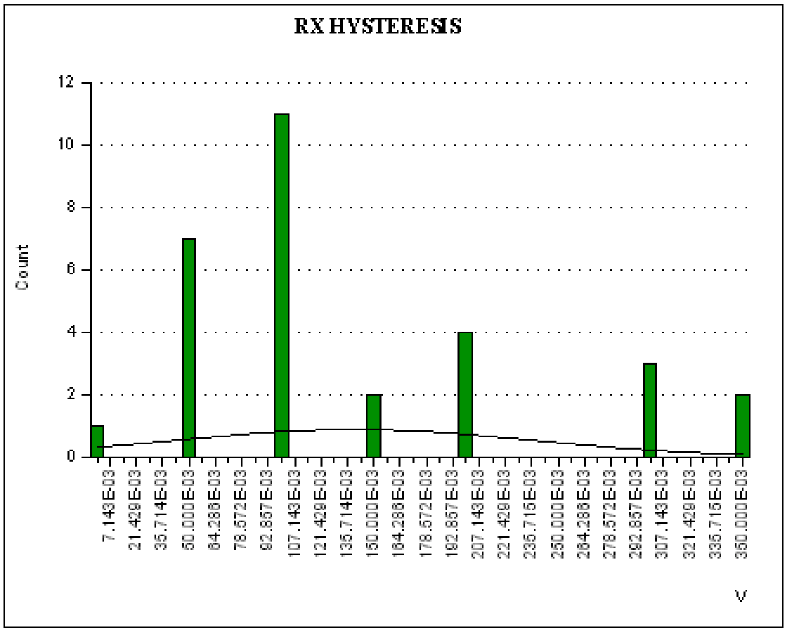
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.011, Test.Name=RX HYSTERESIS



Statistics: (V)

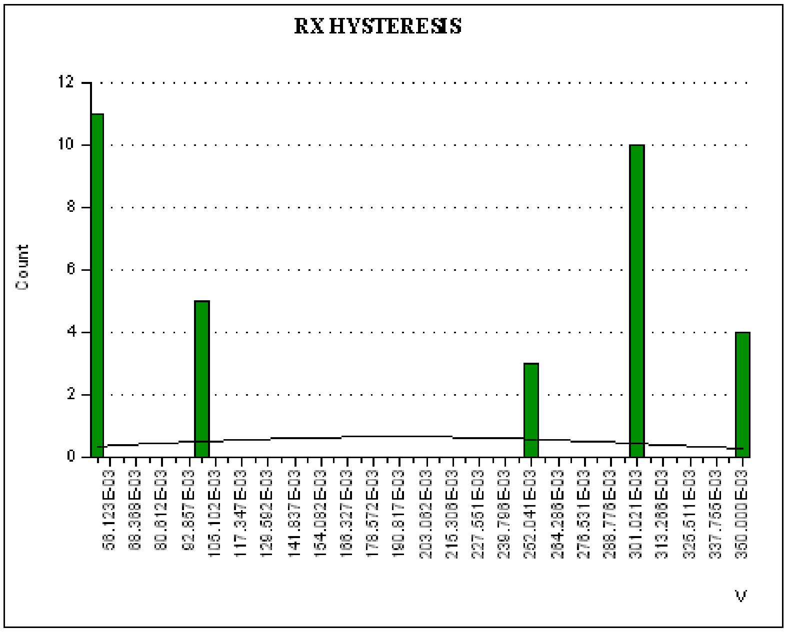
Min	0	**Skew**	0.9884
Max	350.000E-03	**StatHigh**	N/A
Mean	138.334E-03	**StatLow**	N/A
StdDev	97.099E-03	**NWithinSpec**	N/A
25%	50.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	429.631E-03	**90%**	300.001E-03
		Range	350.000E-03
Mean-3*StdDev	-152.963E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.011, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	50.000E-03	**StatLow**	N/A
Max	350.000E-03	**NWithinSpec**	N/A
Mean	187.879E-03	**NOutsideSpec**	N/A
StdDev	123.763E-03	**90%**	350.000E-03
25%	50.000E-03	**Range**	300.000E-03
Mean+3*StdDev	559.169E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-183.410E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0065		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

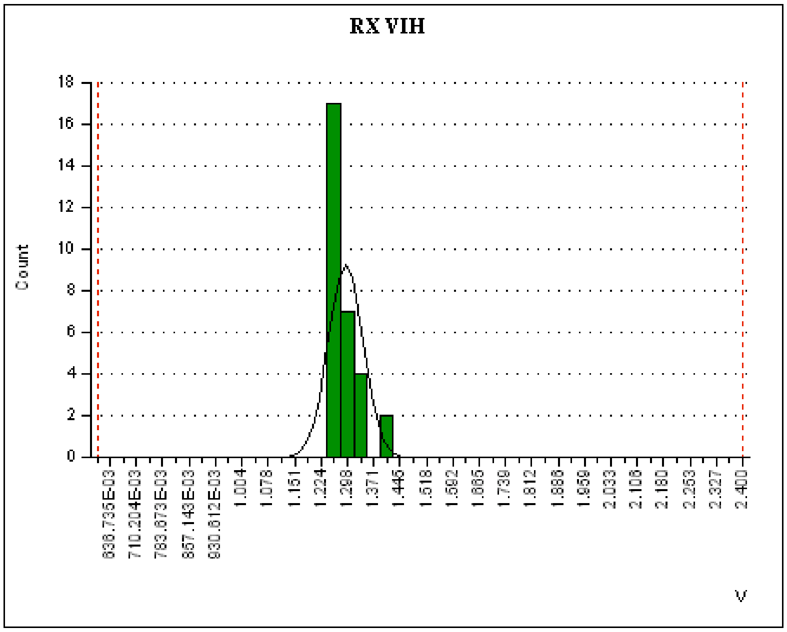
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.012, Test.Name=RX VIH



Statistics: (V)

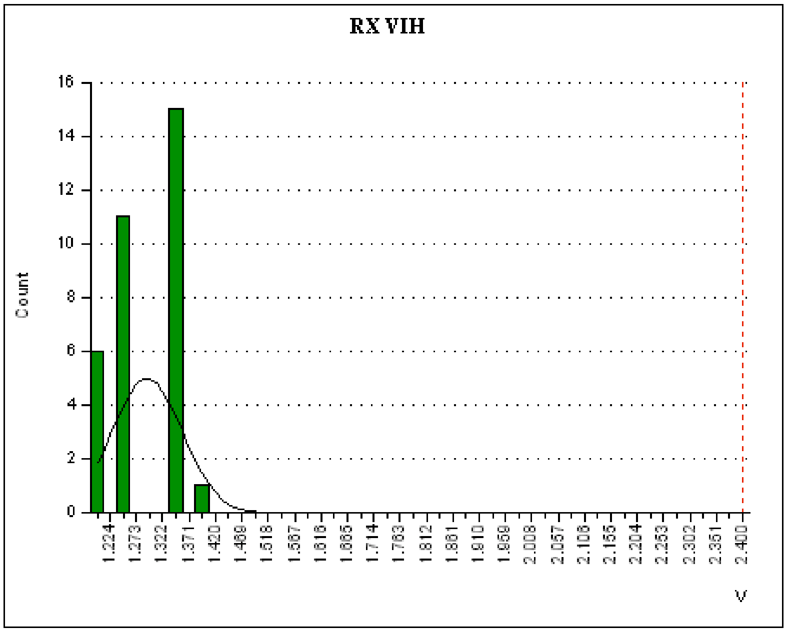
Min	1.250	**Skew**	1.1756
Max	1.400	**StatHigh**	N/A
Mean	1.285	**StatLow**	N/A
StdDev	47.616E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.428	**90%**	1.350
		Range	150.000E-03
Mean-3*StdDev	1.142	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.012, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.400	**NWithinSpec**	33
Mean	1.291	**NOutsideSpec**	0
StdDev	64.293E-03	**90%**	1.350
25%	1.250	**Range**	200.000E-03
Mean+3*StdDev	1.484	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.098	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.1086		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

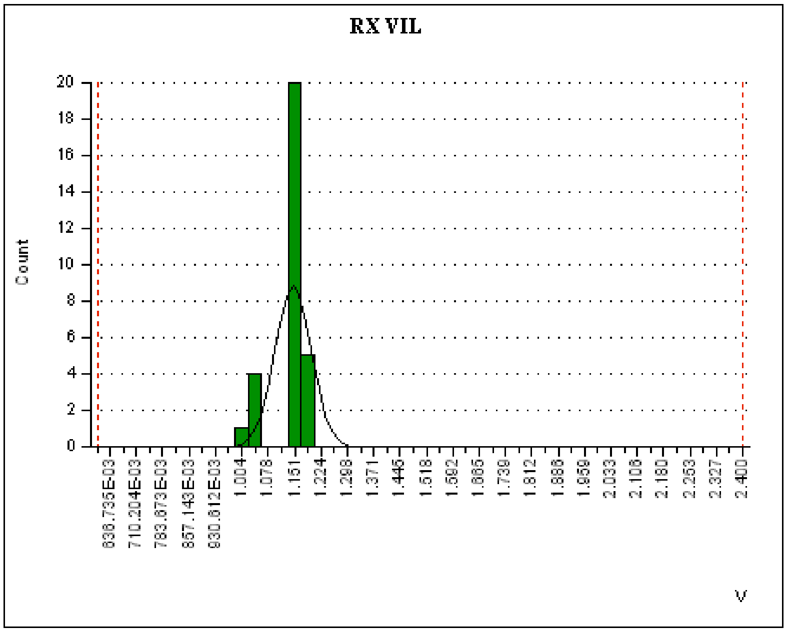
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.013, Test.Name=RX VIL



Statistics: (V)

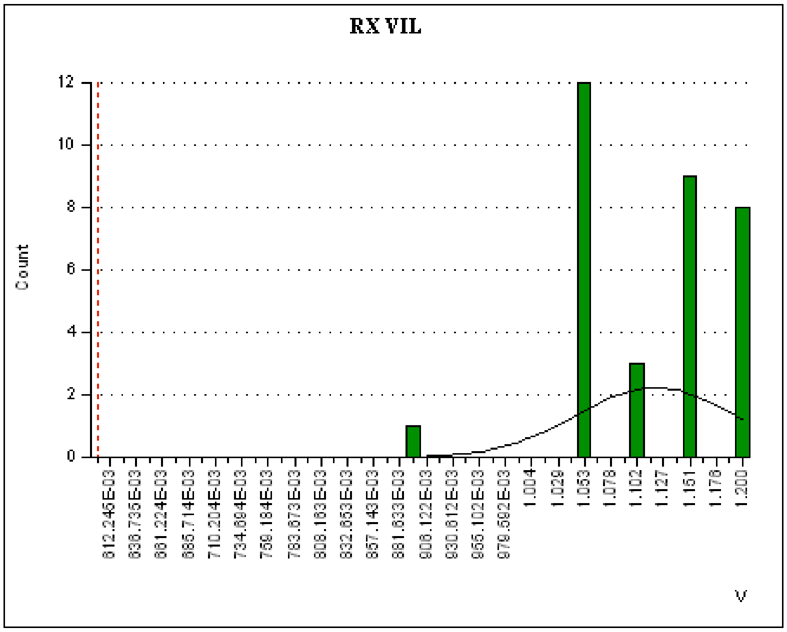
Min	1000.000E-03	**Skew**	-1.3618
Max	1.200	**StatHigh**	N/A
Mean	1.140	**StatLow**	N/A
StdDev	49.827E-03	**NWithinSpec**	30
25%	1.150	**NOutsideSpec**	0
Mean+3*StdDev	1.289	**90%**	1.200
		Range	200.000E-03
Mean-3*StdDev	990.517E-03	**NOutsideSpec**	0
Cpk	3.6125		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.013, Test.Name=RX VIL



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.200	**NWithinSpec**	33
Mean	1.114	**NOutsideSpec**	0
StdDev	72.103E-03	**90%**	1.200
25%	1.050	**Range**	300.000E-03
Mean+3*StdDev	1.330	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	897.326E-03	**Cpl**	2.3745
		Cpu	N/A
Cpk	2.3745		
Skew	-0.6447		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

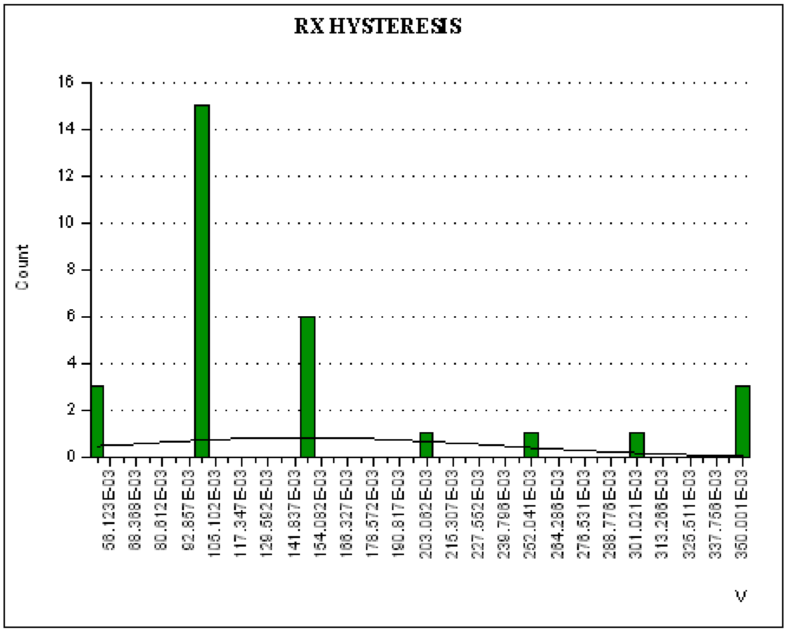
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=10.014, Test.Name=RX HYSTERESIS



Statistics: (V)

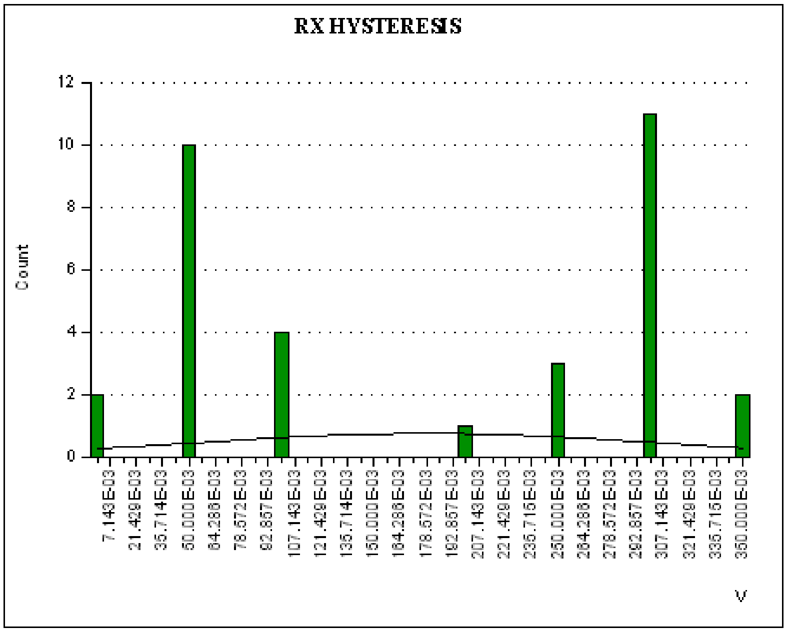
Min	50.000E-03	**Skew**	1.4894
Max	350.001E-03	**StatHigh**	N/A
Mean	145.000E-03	**StatLow**	N/A
StdDev	87.445E-03	**NWithinSpec**	N/A
25%	100.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	407.335E-03	**90%**	325.001E-03
		Range	300.001E-03
Mean-3*StdDev	-117.334E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.014, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	0	**StatLow**	N/A
Max	350.000E-03	**NWithinSpec**	N/A
Mean	177.273E-03	**NOutsideSpec**	N/A
StdDev	123.801E-03	**90%**	300.001E-03
25%	50.000E-03	**Range**	350.000E-03
Mean+3*StdDev	548.678E-03	**NOutsideSpec**	N/A
Mean-3*StdDev	-194.131E-03	**Cp**	N/A
Cpk	N/A	**Cpl**	N/A
Skew	-0.0315	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

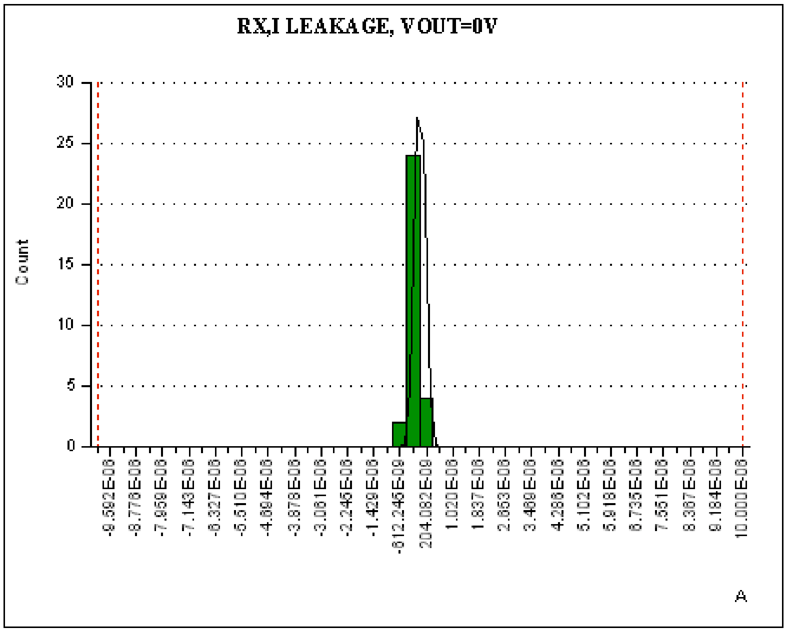
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.000, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

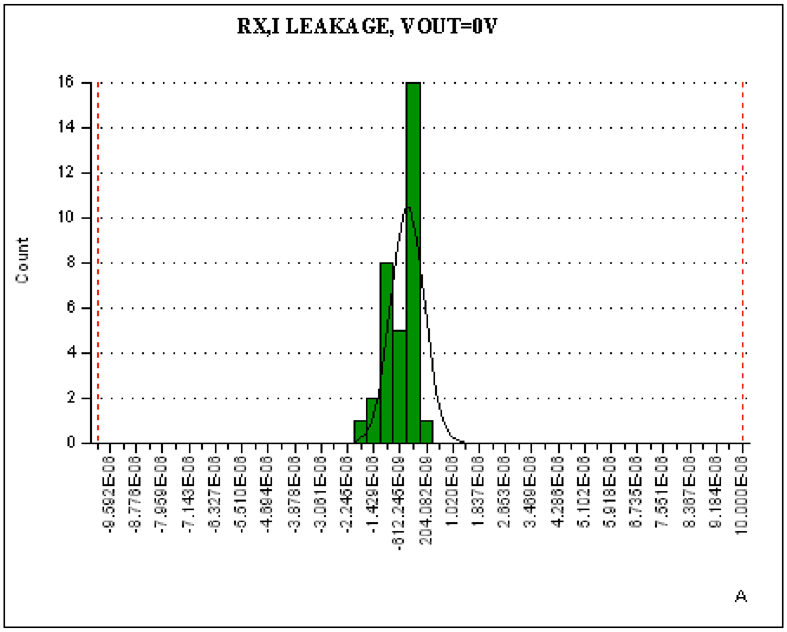
Min	-628.512E-09	**Skew**	-2.3715
Max	5.701E-09	**StatHigh**	N/A
Mean	-108.975E-09	**StatLow**	N/A
StdDev	148.916E-09	**NWithinSpec**	30
25%	-173.384E-09	**NOutsideSpec**	0
Mean+3*StdDev	337.774E-09	**90%**	776.245E-12
		Range	634.213E-09
Mean-3*StdDev	-555.723E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.000, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-1.712E-06	**StatLow**	N/A
Max	506.599E-12	**NWithinSpec**	33
Mean	-490.965E-09	**NOutsideSpec**	0
StdDev	506.993E-09	**90%**	-8.698E-09
25%	-957.537E-09	**Range**	1.713E-06
Mean+3*StdDev	1.030E-06	**NOutsideSpec**	0
Mean-3*StdDev	-2.012E-06	**Cp**	>4.0000
Cpk	>4.0000	**Cpl**	>4.0000
Skew	-0.6902	**Cpu**	>4.0000
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

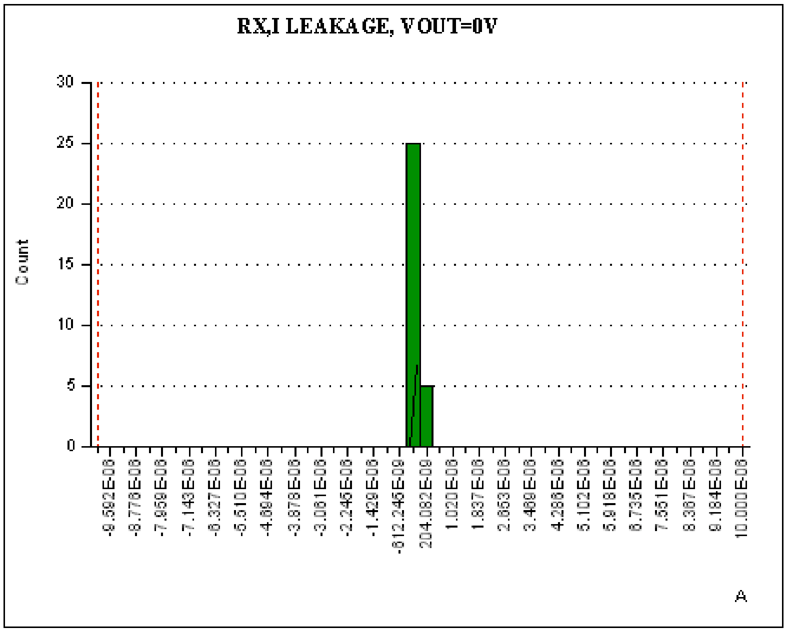
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.001, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

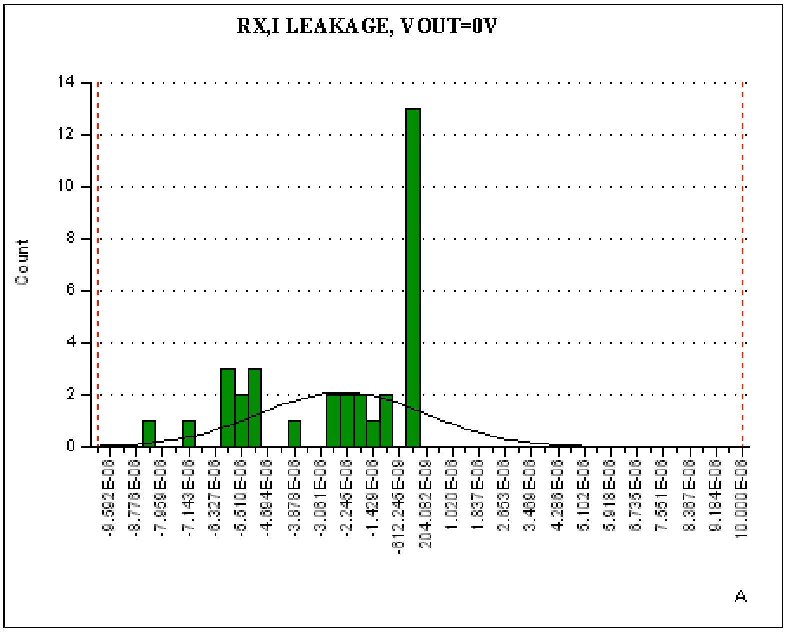
Min	-248.644E-09	**Skew**	-1.6495
Max	8.649E-09	**StatHigh**	N/A
Mean	-58.911E-09	**StatLow**	N/A
StdDev	63.847E-09	**NWithinSpec**	30
25%	-86.802E-09	**NOutsideSpec**	0
Mean+3*StdDev	132.630E-09	**90%**	3.023E-09
		Range	257.292E-09
Mean-3*StdDev	-250.451E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.001, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-8.200E-06	**StatLow**	N/A
Max	-3.363E-09	**NWithinSpec**	33
Mean	-2.452E-06	**NOutsideSpec**	0
StdDev	2.560E-06	**90%**	-12.871E-09
25%	-5.124E-06	**Range**	8.196E-06
Mean+3*StdDev	5.229E-06	**NOutsideSpec**	0
		Cp	1.3019
Mean-3*StdDev	-10.133E-06	**Cpl**	0.9827
		Cpu	1.6211
Cpk	0.9827		
Skew	-0.6585		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

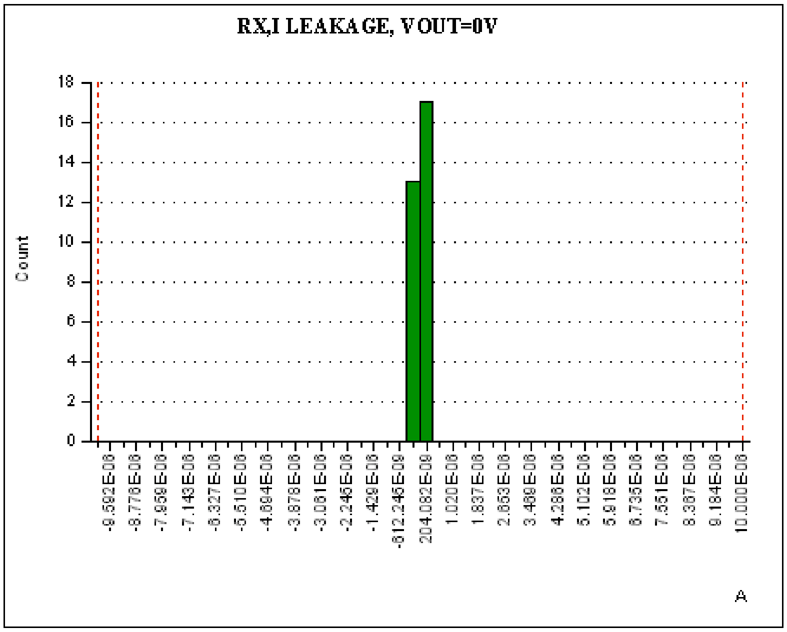
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.002, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

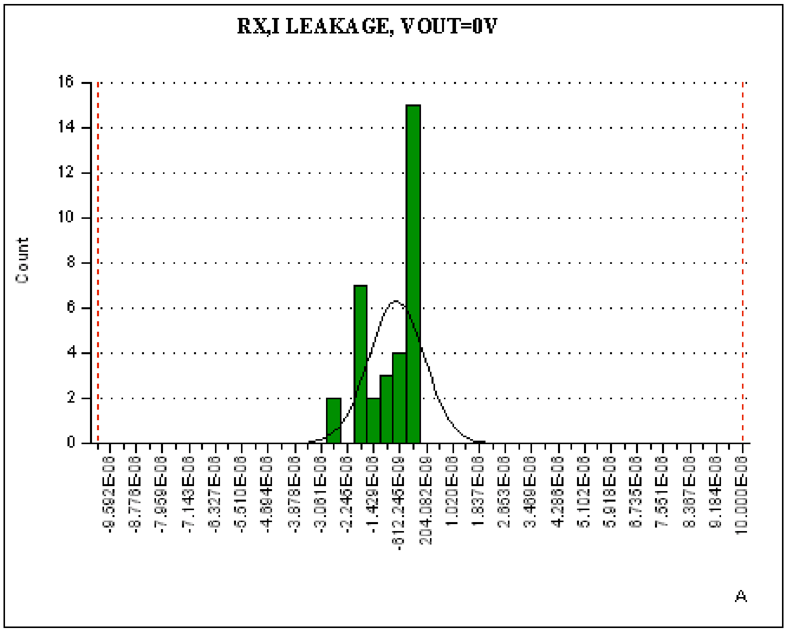
Min	-70.393E-09	**Skew**	-2.0834
Max	24.318E-09	**StatHigh**	N/A
Mean	-2.185E-09	**StatLow**	N/A
StdDev	20.860E-09	**NWithinSpec**	30
25%	-6.654E-09	**NOutsideSpec**	0
Mean+3*StdDev	60.393E-09	**90%**	17.122E-09
		Range	94.711E-09
Mean-3*StdDev	-64.764E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.002, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-2.685E-06	**StatLow**	N/A
Max	-1.496E-09	**NWithinSpec**	33
Mean	-826.728E-09	**NOutsideSpec**	0
StdDev	848.225E-09	**90%**	-6.440E-09
25%	-1.662E-06	**Range**	2.684E-06
Mean+3*StdDev	1.718E-06	**NOutsideSpec**	0
		Cp	3.9298
Mean-3*StdDev	-3.371E-06	**Cpl**	3.6049
Cpk	3.6049	**Cpu**	>4.0000
Skew	-0.6516		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

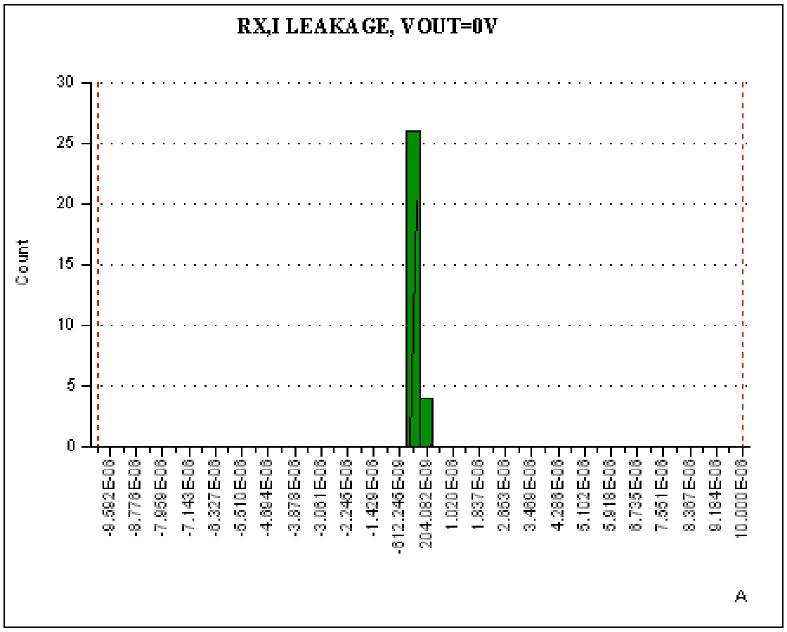
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.003, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

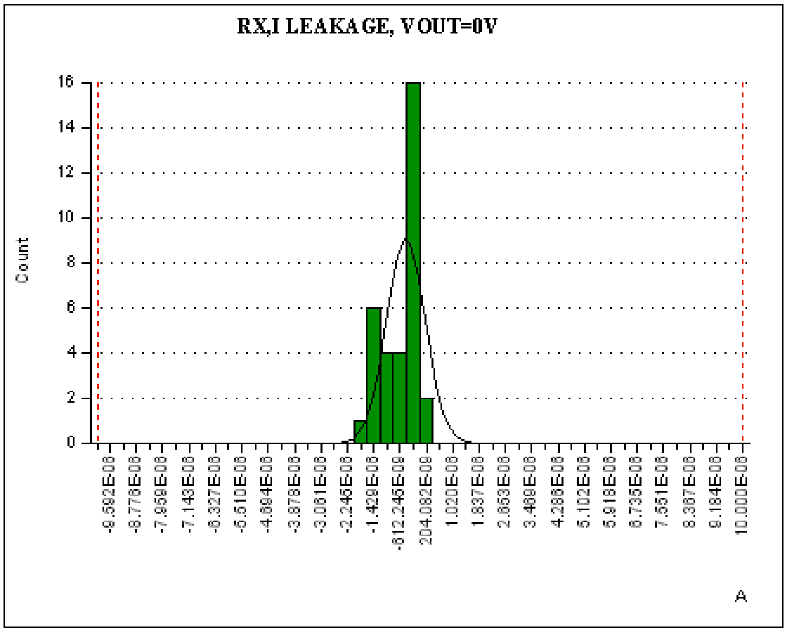
Min	-296.325E-09	**Skew**	-1.1278
Max	11.965E-09	**StatHigh**	N/A
Mean	-79.913E-09	**StatLow**	N/A
StdDev	81.806E-09	**NWithinSpec**	30
25%	-131.505E-09	**NOutsideSpec**	0
Mean+3*StdDev	165.505E-09	**90%**	2.875E-09
		Range	308.290E-09
Mean-3*StdDev	-325.331E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.003, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-1.966E-06	**StatLow**	N/A
Max	4.582E-09	**NWithinSpec**	33
Mean	-545.537E-09	**NOutsideSpec**	0
StdDev	590.937E-09	**90%**	-3.656E-09
25%	-1.059E-06	**Range**	1.971E-06
Mean+3*StdDev	1.227E-06	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-2.318E-06	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.7736		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

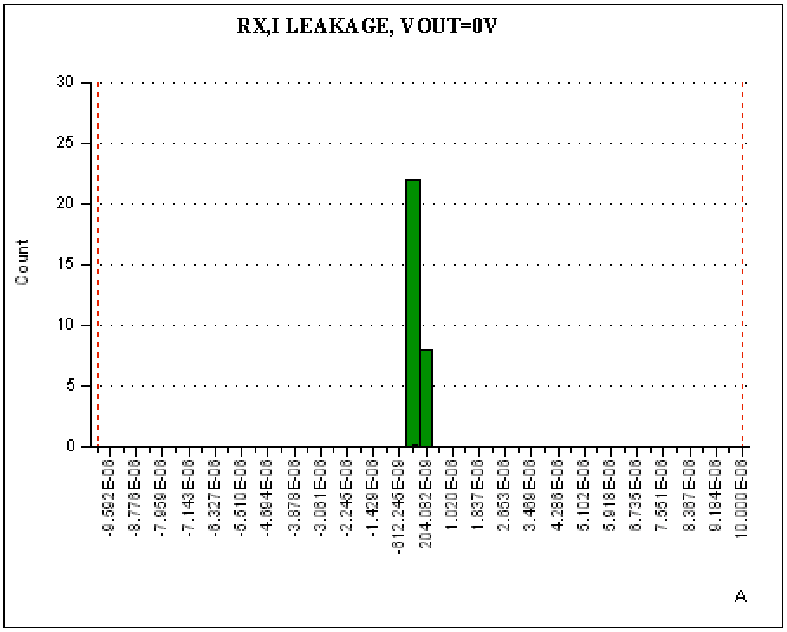
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.004, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

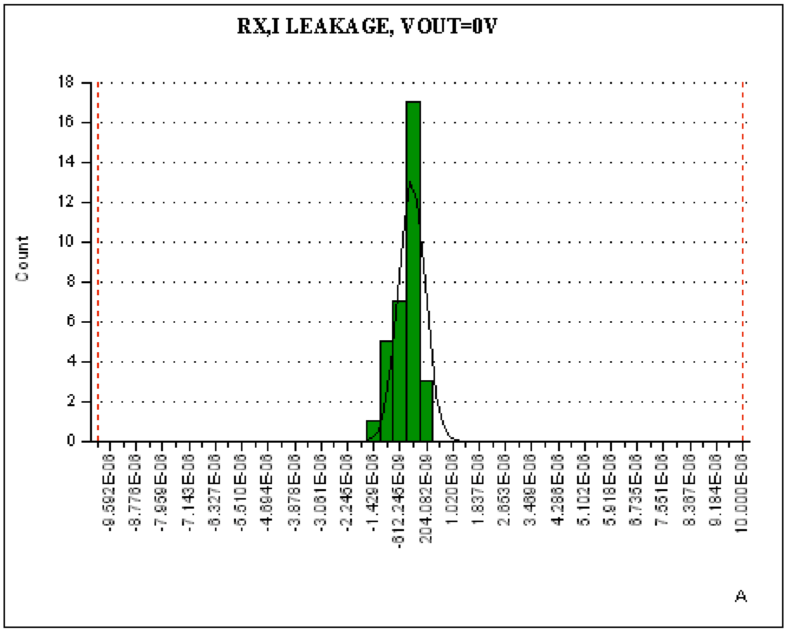
Min	-163.021E-09	**Skew**	-1.4659
Max	20.537E-09	**StatHigh**	N/A
Mean	-33.841E-09	**StatLow**	N/A
StdDev	43.938E-09	**NWithinSpec**	30
25%	-54.034E-09	**NOutsideSpec**	0
Mean+3*StdDev	97.972E-09	**90%**	4.855E-09
		Range	183.557E-09
Mean-3*StdDev	-165.655E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.004, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-1.356E-06	**StatLow**	N/A
Max	26.114E-09	**NWithinSpec**	33
Mean	-361.401E-09	**NOutsideSpec**	0
StdDev	411.079E-09	**90%**	-3.303E-09
25%	-714.618E-09	**Range**	1.382E-06
Mean+3*StdDev	871.837E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-1.595E-06	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.8170		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

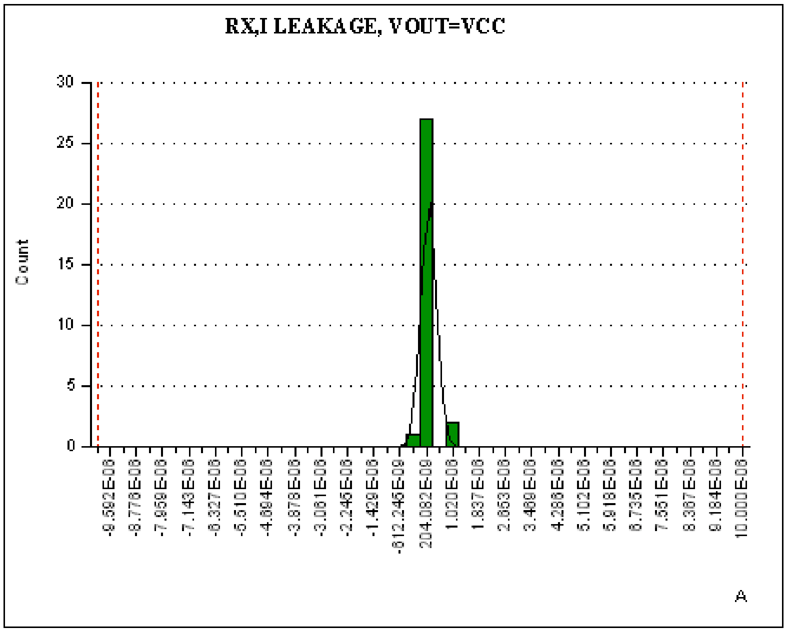
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.005, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

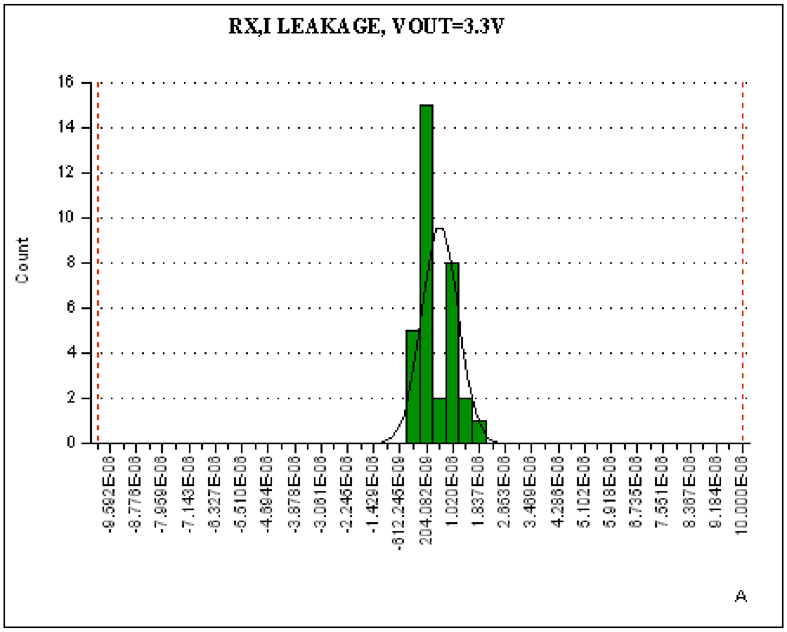
Min	-1.250E-09	**Skew**	2.8456
Max	1.006E-06	**StatHigh**	N/A
Mean	162.680E-09	**StatLow**	N/A
StdDev	239.087E-09	**NWithinSpec**	30
25%	17.932E-09	**NOutsideSpec**	0
Mean+3*StdDev	879.941E-09	**90%**	273.140E-09
		Range	1.007E-06
Mean-3*StdDev	-554.581E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.005, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-17.386E-09	**StatLow**	N/A
Max	1.990E-06	**NWithinSpec**	33
Mean	503.058E-09	**NOutsideSpec**	0
StdDev	552.837E-09	**90%**	1.165E-06
25%	14.188E-09	**Range**	2.007E-06
Mean+3*StdDev	2.162E-06	**NOutsideSpec**	0
		Cp	>4.0000
		Cpl	>4.0000
Mean-3*StdDev	-1.155E-06	**Cpu**	>4.0000
Cpk	>4.0000		
Skew	0.8954		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

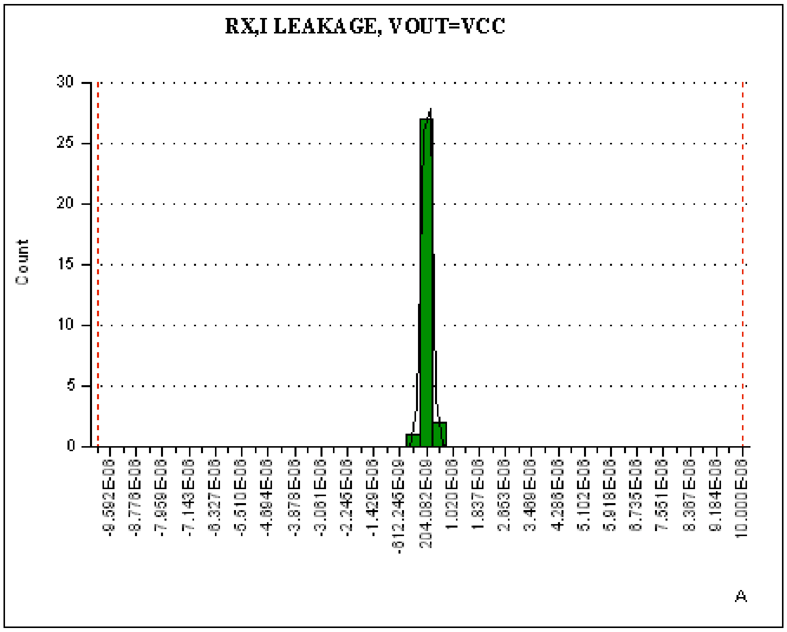
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.006, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

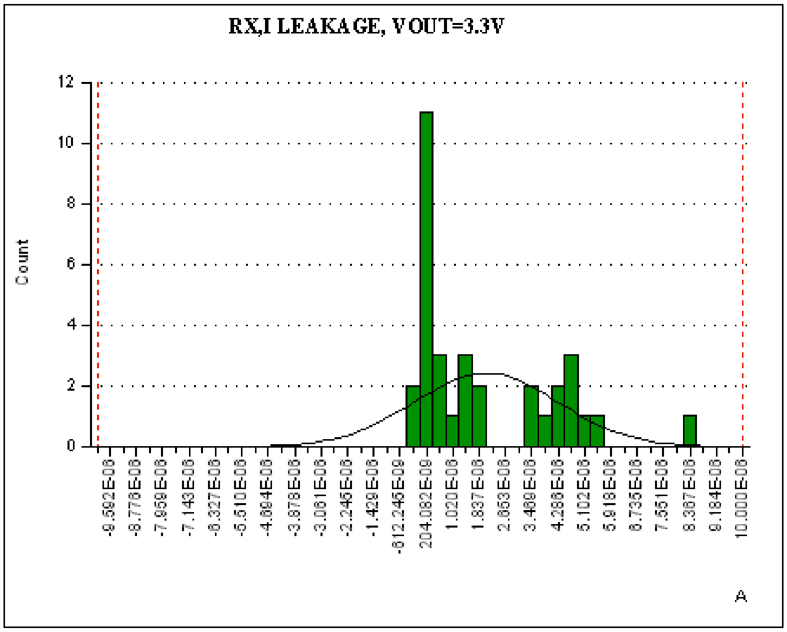
Min	-1.914E-09	**Skew**	2.7025
Max	616.452E-09	**StatHigh**	N/A
Mean	106.885E-09	**StatLow**	N/A
StdDev	141.392E-09	**NWithinSpec**	30
25%	19.357E-09	**NOutsideSpec**	0
Mean+3*StdDev	531.062E-09	**90%**	194.332E-09
		Range	618.366E-09
Mean-3*StdDev	-317.292E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.006, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-22.100E-09	**StatLow**	N/A
Max	8.186E-06	**NWithinSpec**	33
Mean	1.931E-06	**NOutsideSpec**	0
StdDev	2.213E-06	**90%**	4.891E-06
25%	31.533E-09	**Range**	8.208E-06
Mean+3*StdDev	8.570E-06	**NOutsideSpec**	0
		Cp	1.5064
Mean-3*StdDev	-4.707E-06	**Cpl**	1.7973
		Cpu	1.2155
Cpk	1.2155		
Skew	1.0184		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

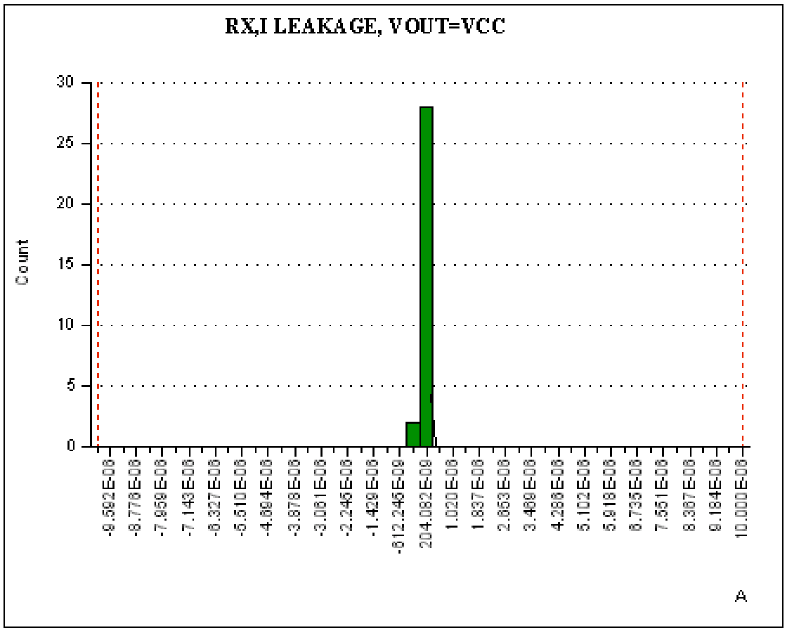
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.007, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

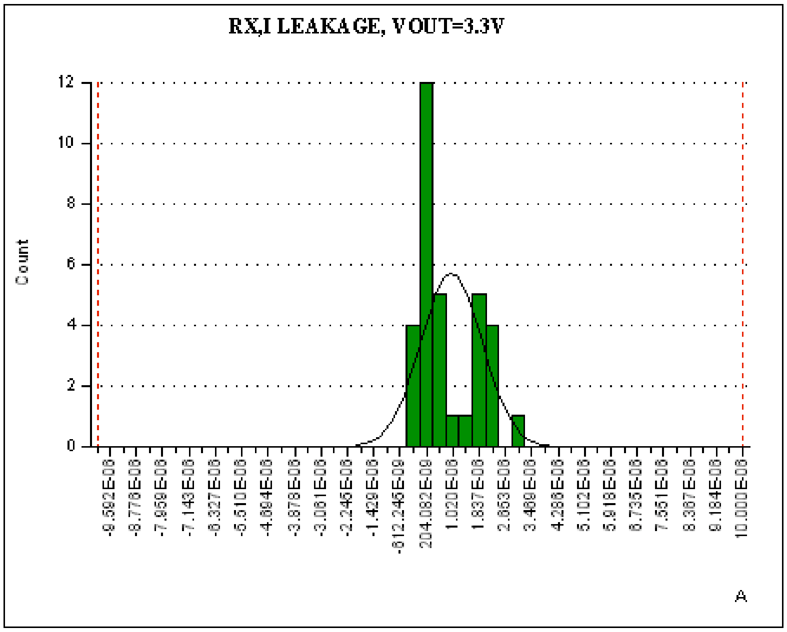
Min	-5.451E-09	**Skew**	2.5195
Max	261.693E-09	**StatHigh**	N/A
Mean	46.693E-09	**StatLow**	N/A
StdDev	63.824E-09	**NWithinSpec**	30
25%	8.206E-09	**NOutsideSpec**	0
Mean+3*StdDev	238.165E-09	**90%**	81.600E-09
		Range	267.143E-09
Mean-3*StdDev	-144.779E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.007, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-14.214E-09	**StatLow**	N/A
Max	3.179E-06	**NWithinSpec**	33
Mean	859.915E-09	**NOutsideSpec**	0
StdDev	936.658E-09	**90%**	2.168E-06
25%	26.980E-09	**Range**	3.193E-06
Mean+3*StdDev	3.670E-06	**NOutsideSpec**	0
		Cp	3.5588
Mean-3*StdDev	-1.950E-06	**Cpl**	3.8648
Cpk	3.2527	**Cpu**	3.2527
Skew	0.8117		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

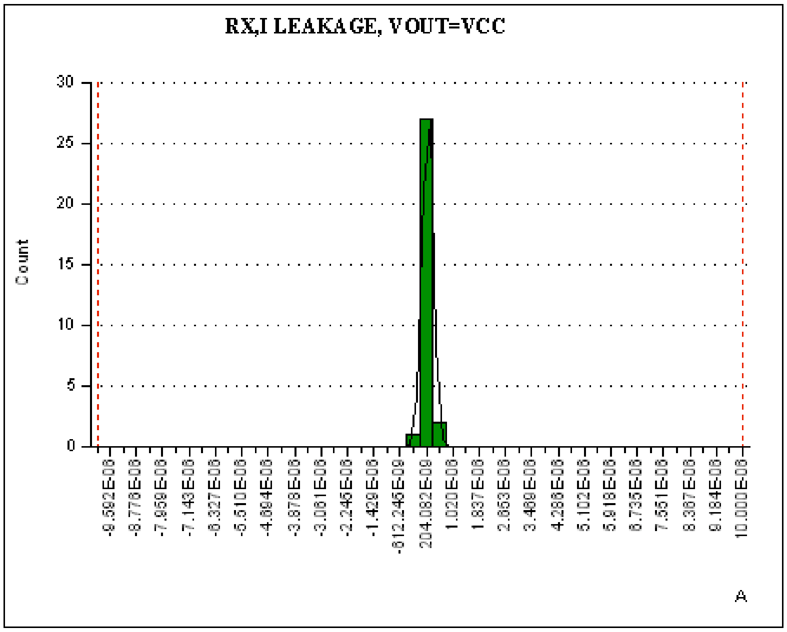
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.008, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

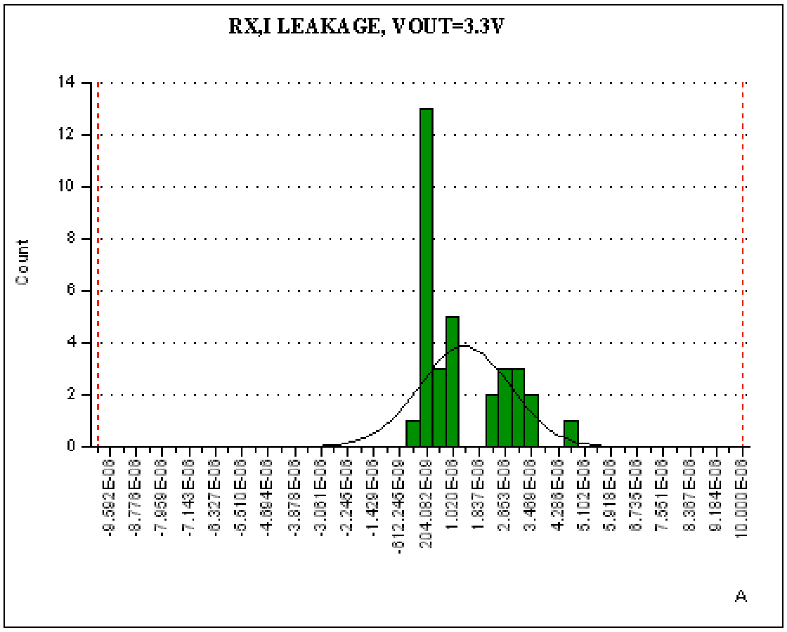
Min	-1.986E-09	**Skew**	2.3141
Max	690.682E-09	**StatHigh**	N/A
Mean	133.004E-09	**StatLow**	N/A
StdDev	168.026E-09	**NWithinSpec**	30
25%	20.316E-09	**NOutsideSpec**	0
Mean+3*StdDev	637.082E-09	**90%**	263.046E-09
		Range	692.668E-09
Mean-3*StdDev	-371.073E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.008, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-6.304E-09	**StatLow**	N/A
Max	4.793E-06	**NWithinSpec**	33
Mean	1.264E-06	**NOutsideSpec**	0
StdDev	1.387E-06	**90%**	3.173E-06
25%	31.753E-09	**Range**	4.799E-06
Mean+3*StdDev	5.424E-06	**NOutsideSpec**	0
		Cp	2.4035
Mean-3*StdDev	-2.897E-06	**Cpl**	2.7072
Cpk	2.0998	**Cpu**	2.0998
Skew	0.8523		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

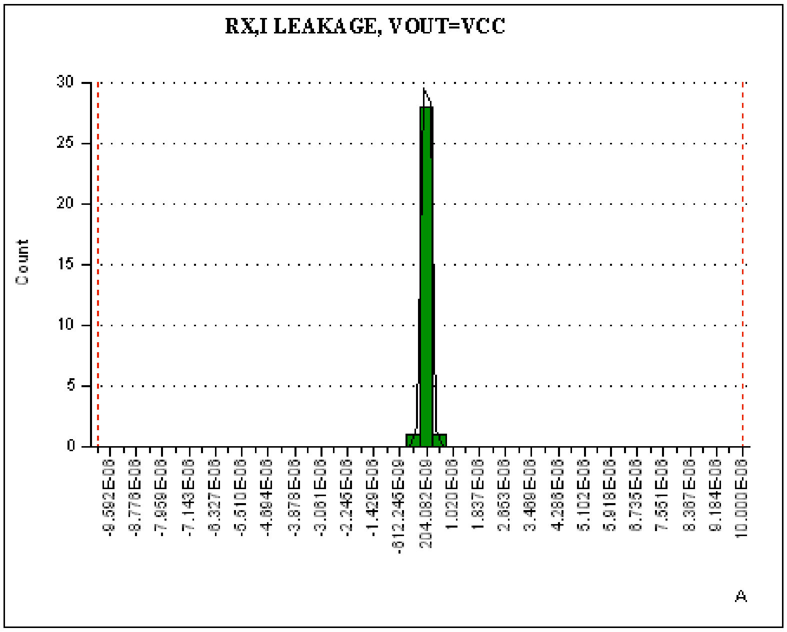
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=11.009, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

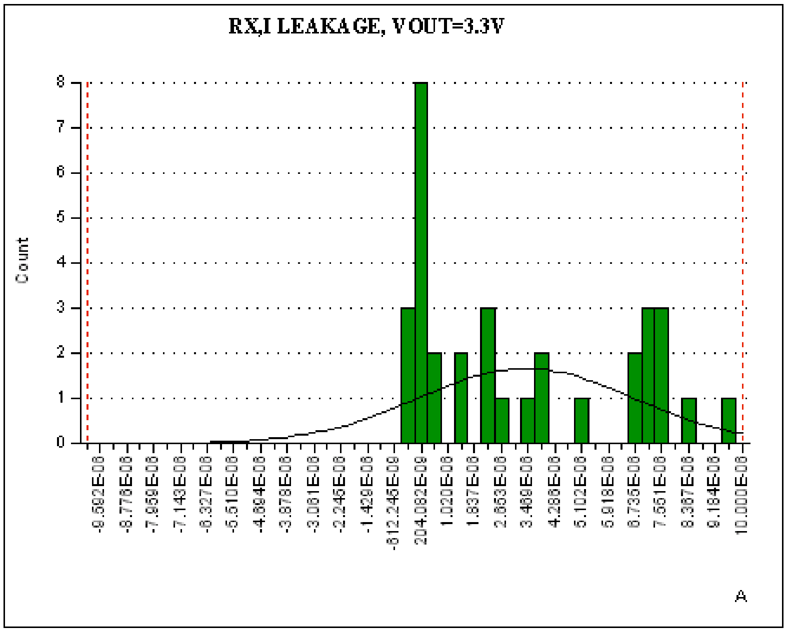
Min	-636.056E-12	**Skew**	1.8626
Max	474.505E-09	**StatHigh**	N/A
Mean	97.068E-09	**StatLow**	N/A
StdDev	117.427E-09	**NWithinSpec**	30
25%	14.643E-09	**NOutsideSpec**	0
Mean+3*StdDev	449.347E-09	**90%**	233.913E-09
		Range	475.141E-09
Mean-3*StdDev	-255.212E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.009, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-17.669E-09	**StatLow**	N/A
Max	9.730E-06	**NWithinSpec**	33
Mean	3.266E-06	**NOutsideSpec**	0
StdDev	3.232E-06	**90%**	7.650E-06
25%	174.876E-09	**Range**	9.748E-06
Mean+3*StdDev	12.961E-06	**NOutsideSpec**	0
		Cp	1.0315
Mean-3*StdDev	-6.429E-06	**Cpl**	1.3684
		Cpu	0.6946
Cpk	0.6946		
Skew	0.5088		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

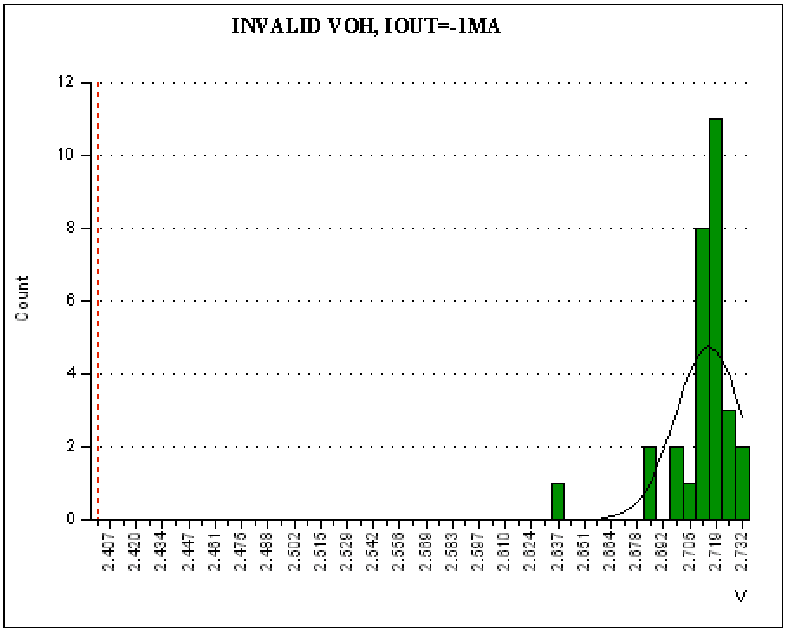
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=12.001, Test.Name=INVALID VOH, IOUT=-1MA



Statistics: (V)

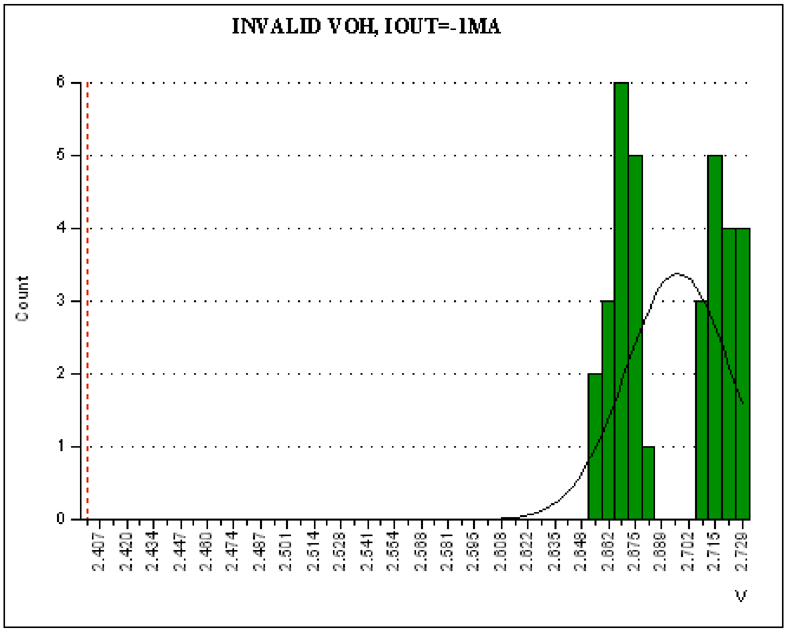
Min	2.640	**Skew**	-2.7449
Max	2.732	**StatHigh**	N/A
Mean	2.711	**StatLow**	N/A
StdDev	17.070E-03	**NWithinSpec**	30
25%	2.709	**NOutsideSpec**	0
Mean+3*StdDev	2.763	**90%**	2.725
		Range	92.042E-03
Mean-3*StdDev	2.660	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=12.001, Test.Name=INVALID VOH, IOUT=-1MA



Statistics: (V)

Min	2.654	**StatLow**	N/A
Max	2.729	**NWithinSpec**	33
Mean	2.693	**NOutsideSpec**	0
StdDev	26.138E-03	**90%**	2.726
25%	2.668	**Range**	74.700E-03
Mean+3*StdDev	2.772	**NOutsideSpec**	0
Mean-3*StdDev	2.615	**Cp**	N/A
Cpk	3.7428	**Cpl**	3.7428
Skew	0.0198	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

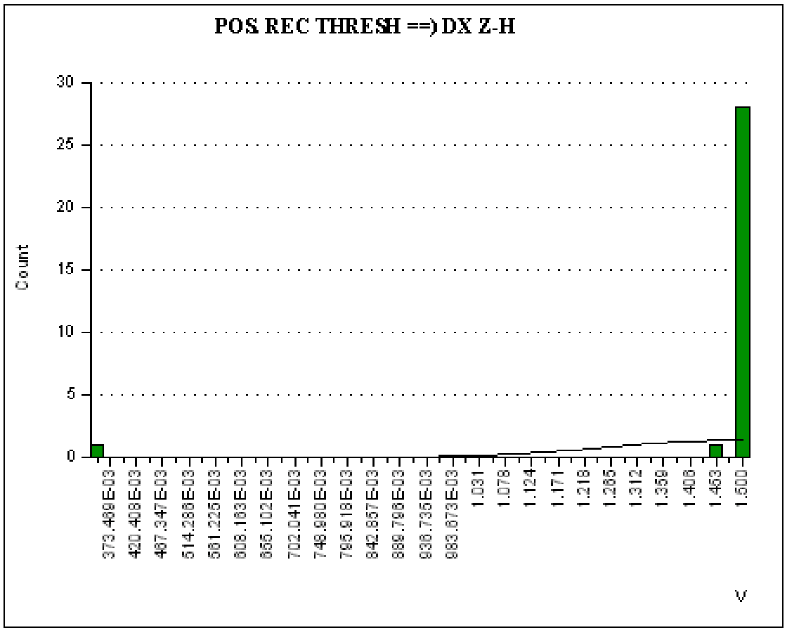
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.000, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

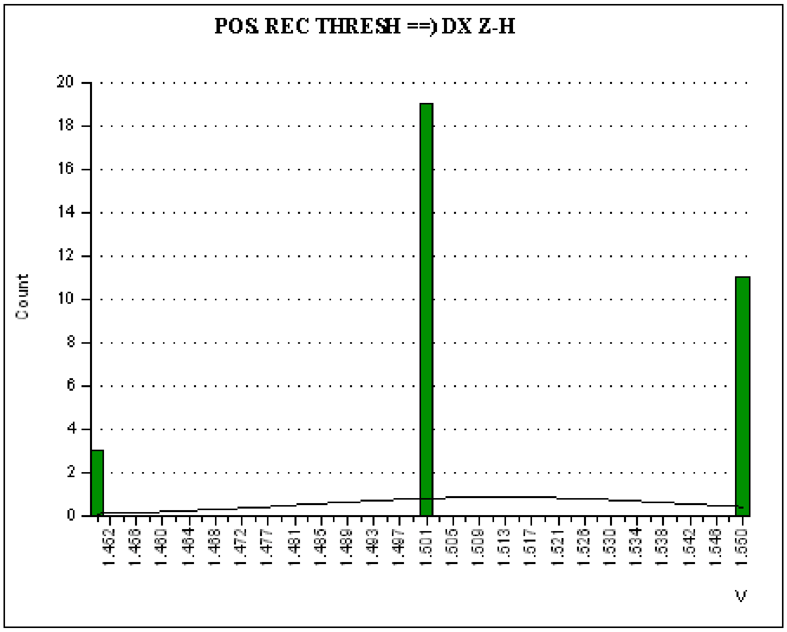
Min	350.000E-03	**Skew**	-5.4610
Max	1.500	**StatHigh**	N/A
Mean	1.460	**StatLow**	N/A
StdDev	209.844E-03	**NWithinSpec**	N/A
25%	1.500	**NOutsideSpec**	N/A
Mean+3*StdDev	2.090	**90%**	1.500
		Range	1.150
Mean-3*StdDev	830.468E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.000, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.450	**StatLow**	N/A
Max	1.550	**NWithinSpec**	N/A
Mean	1.512	**NOutsideSpec**	N/A
StdDev	30.696E-03	**90%**	1.550
25%	1.500	**Range**	100.000E-03
Mean+3*StdDev	1.604	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.420	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.1785		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

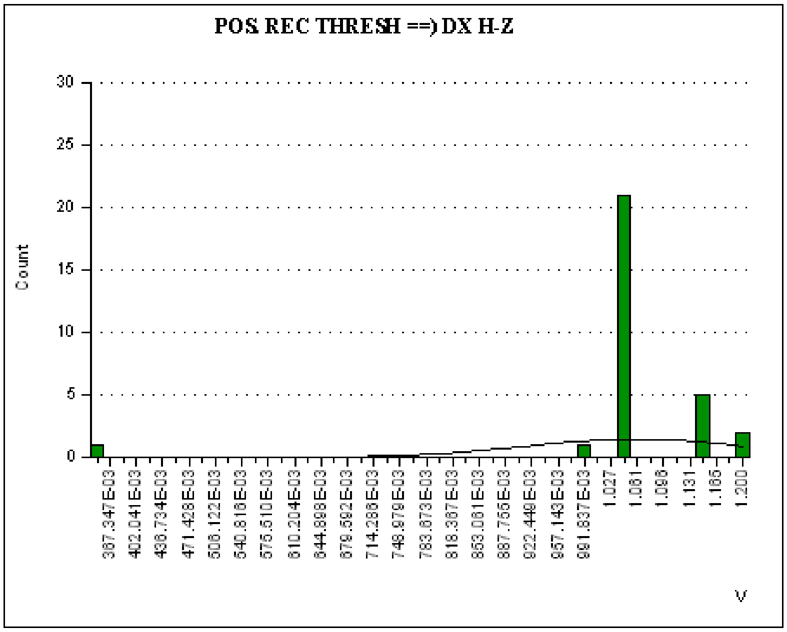
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.001, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

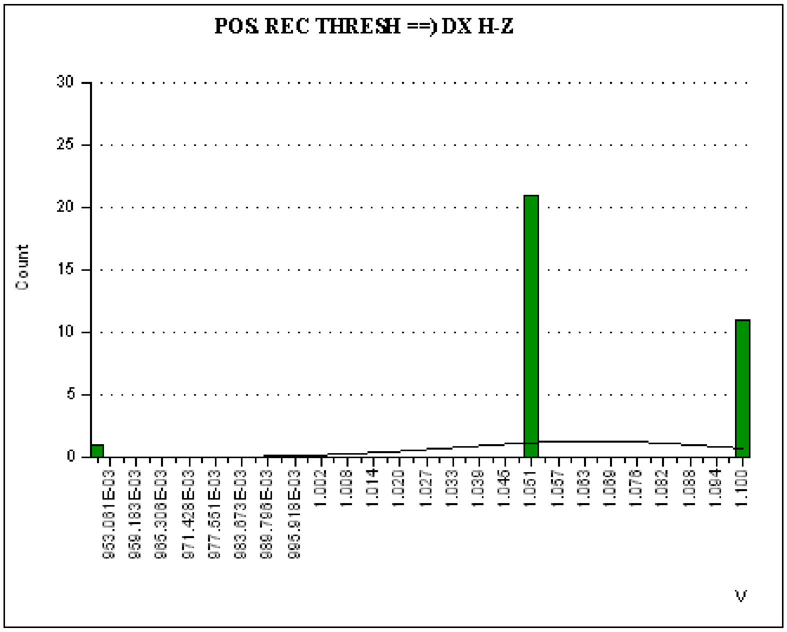
Min	350.000E-03	**Skew**	-4.2845
Max	1.200	**StatHigh**	N/A
Mean	1.052	**StatLow**	N/A
StdDev	142.323E-03	**NWithinSpec**	N/A
25%	1.050	**NOutsideSpec**	N/A
Mean+3*StdDev	1.479	**90%**	1.150
		Range	850.000E-03
Mean-3*StdDev	624.699E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.001, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.100	**NWithinSpec**	N/A
Mean	1.064	**NOutsideSpec**	N/A
StdDev	31.307E-03	**90%**	1.100
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.158	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	969.717E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.0752		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

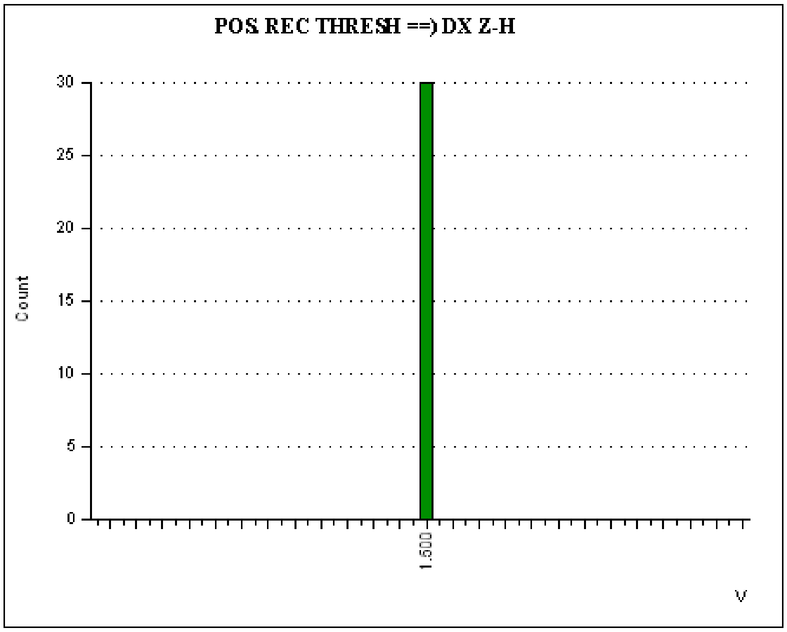
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.002, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

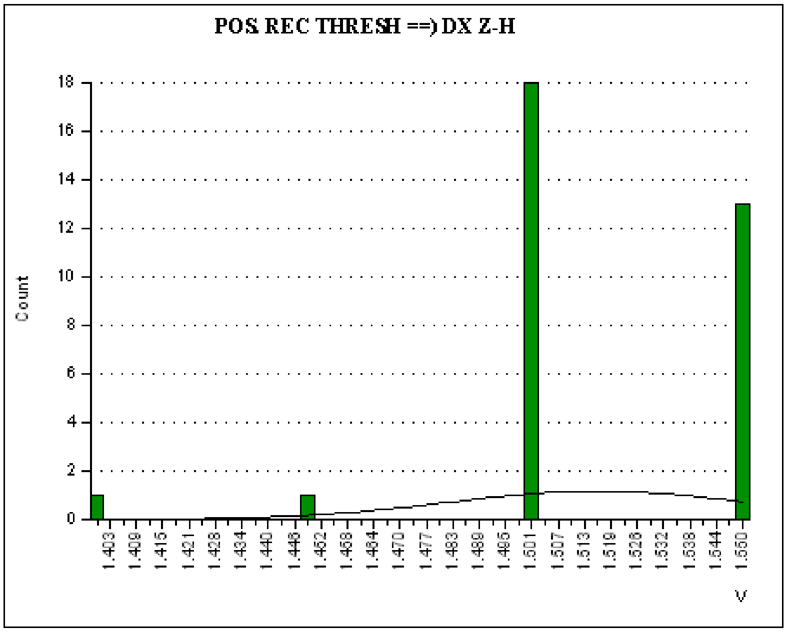
Min	1.500	**Skew**	N/A
Max	1.500	**StatHigh**	N/A
Mean	1.500	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	1.500	**NOutsideSpec**	N/A
Mean+3*StdDev	1.500	**90%**	1.500
		Range	0
Mean-3*StdDev	1.500	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.002, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.400	**StatLow**	N/A
Max	1.550	**NWithinSpec**	N/A
Mean	1.515	**NOutsideSpec**	N/A
StdDev	34.198E-03	**90%**	1.550
25%	1.500	**Range**	150.001E-03
Mean+3*StdDev	1.618	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.413	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-1.0945		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

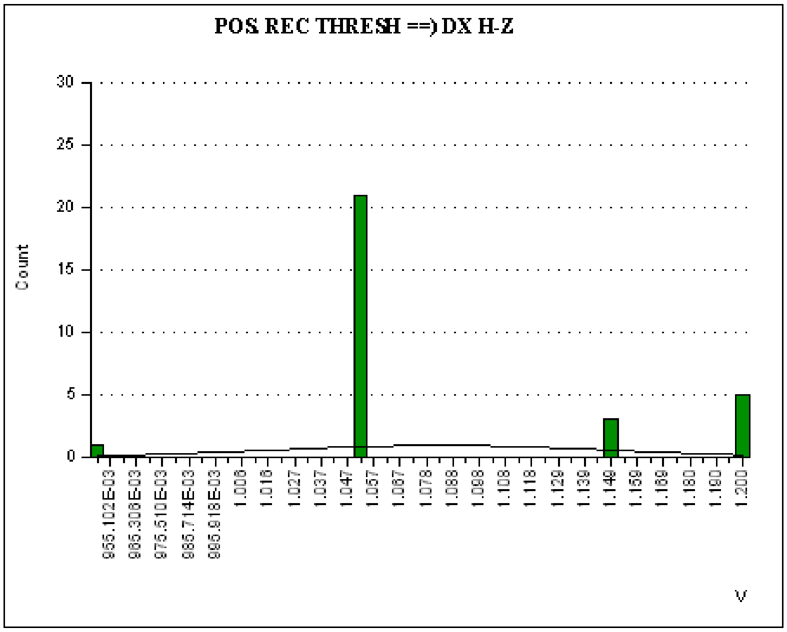
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.003, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

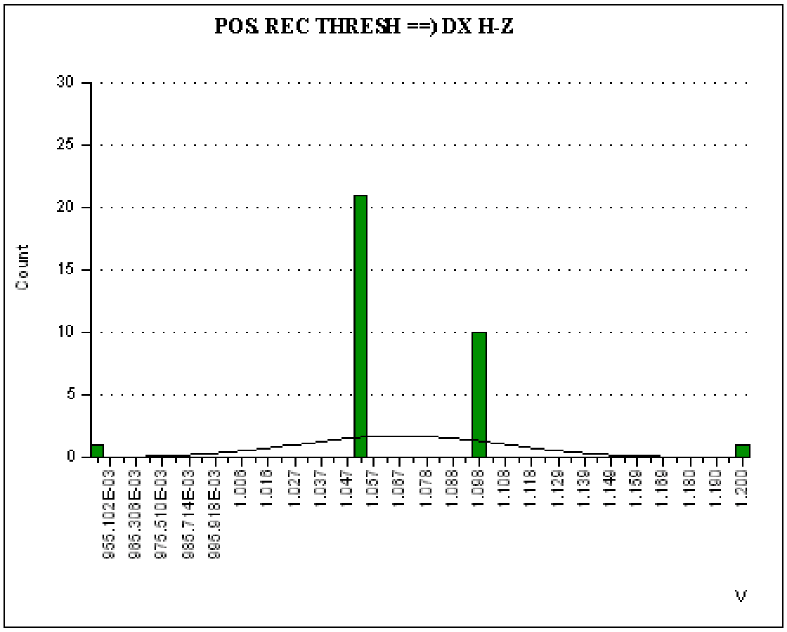
Min	950.000E-03	**Skew**	0.8477
Max	1.200	**StatHigh**	N/A
Mean	1.082	**StatLow**	N/A
StdDev	64.971E-03	**NWithinSpec**	N/A
25%	1.050	**NOutsideSpec**	N/A
Mean+3*StdDev	1.277	**90%**	1.200
		Range	250.000E-03
Mean-3*StdDev	886.753E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.003, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.200	**NWithinSpec**	N/A
Mean	1.067	**NOutsideSpec**	N/A
StdDev	38.864E-03	**90%**	1.100
25%	1.050	**Range**	250.000E-03
Mean+3*StdDev	1.183	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	950.075E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.5982		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

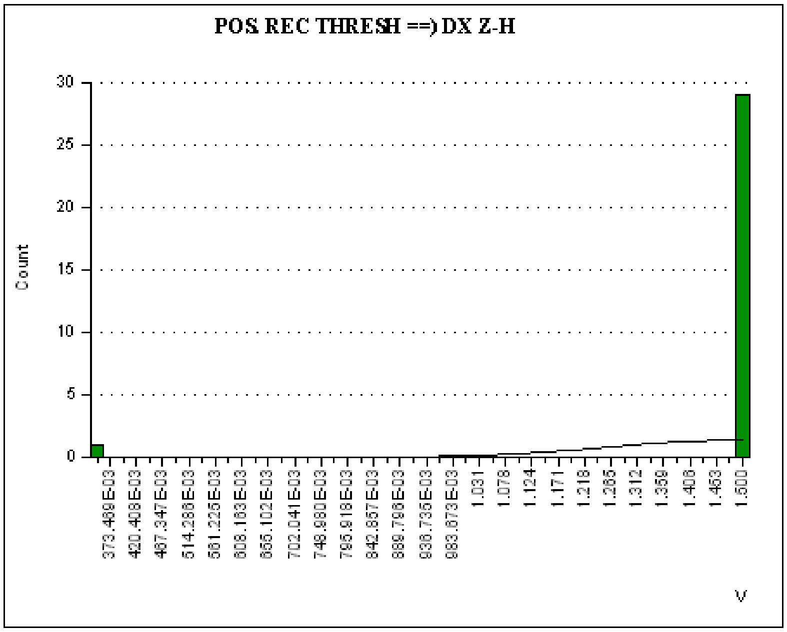
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.004, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

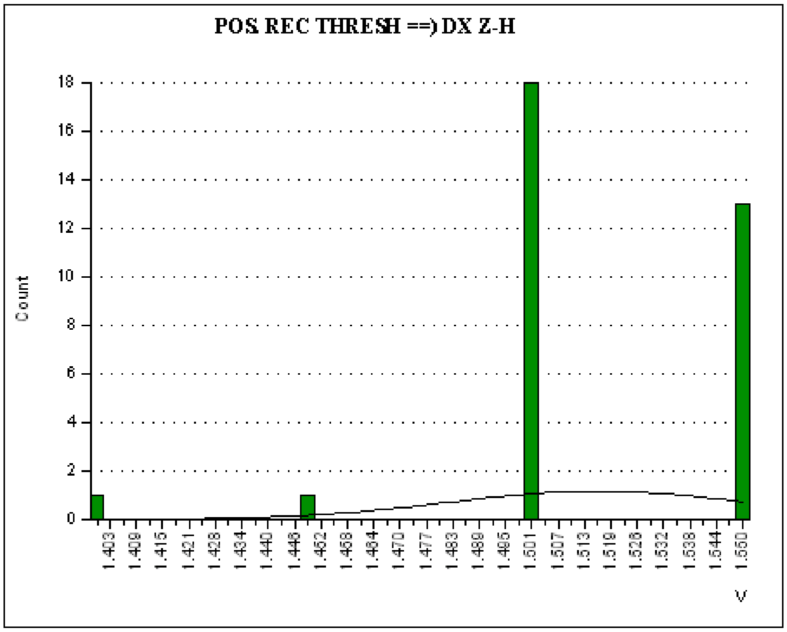
Min	350.000E-03	**Skew**	-5.4772
Max	1.500	**StatHigh**	N/A
Mean	1.462	**StatLow**	N/A
StdDev	209.960E-03	**NWithinSpec**	N/A
25%	1.500	**NOutsideSpec**	N/A
Mean+3*StdDev	2.092	**90%**	1.500
		Range	1.150
Mean-3*StdDev	831.786E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.004, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.400	**StatLow**	N/A
Max	1.550	**NWithinSpec**	N/A
Mean	1.515	**NOutsideSpec**	N/A
StdDev	34.198E-03	**90%**	1.550
25%	1.500	**Range**	150.001E-03
Mean+3*StdDev	1.618	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.413	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.0945		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

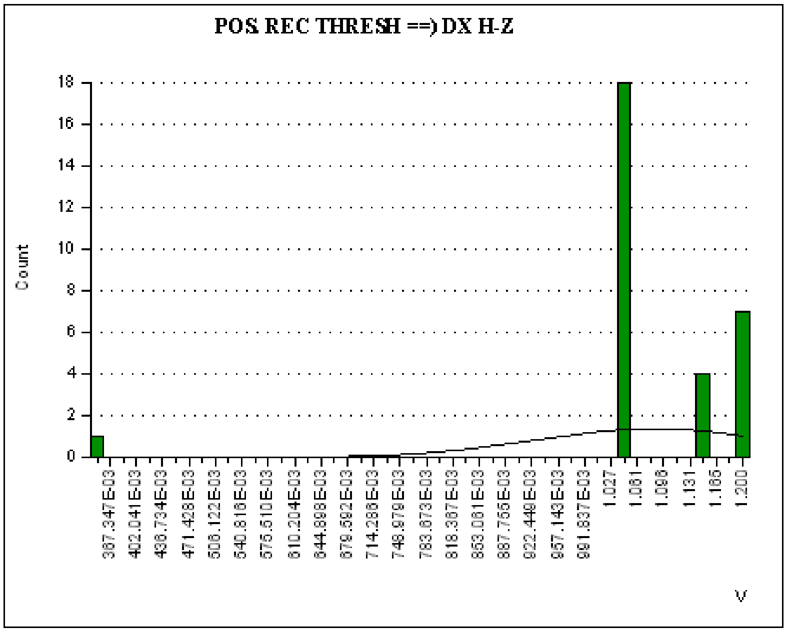
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.005, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

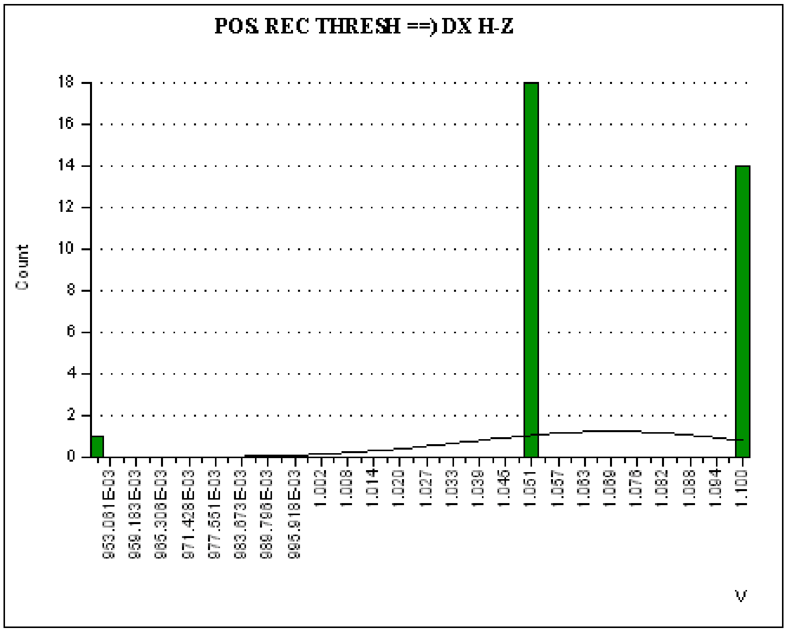
Min	350.000E-03	**Skew**	-3.8614
Max	1.200	**StatHigh**	N/A
Mean	1.075	**StatLow**	N/A
StdDev	151.856E-03	**NWithinSpec**	N/A
25%	1.050	**NOutsideSpec**	N/A
Mean+3*StdDev	1.531	**90%**	1.200
		Range	850.000E-03
Mean-3*StdDev	619.431E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.005, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.100	**NWithinSpec**	N/A
Mean	1.068	**NOutsideSpec**	N/A
StdDev	32.639E-03	**90%**	1.100
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.166	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	970.264E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.2512		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

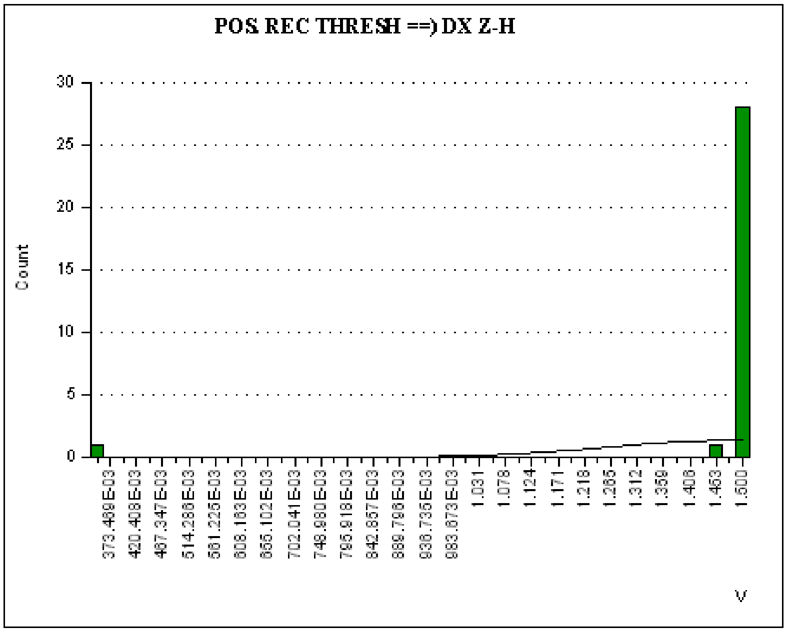
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.006, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

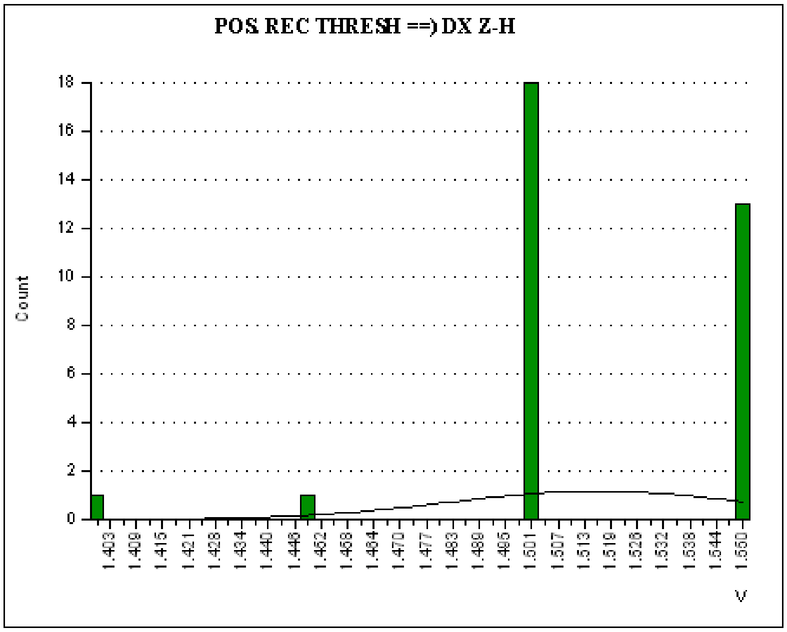
Min	350.000E-03	**Skew**	-5.4610
Max	1.500	**StatHigh**	N/A
Mean	1.460	**StatLow**	N/A
StdDev	209.844E-03	**NWithinSpec**	N/A
25%	1.500	**NOutsideSpec**	N/A
Mean+3*StdDev	2.090	**90%**	1.500
		Range	1.150
Mean-3*StdDev	830.468E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.006, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.400	**StatLow**	N/A
Max	1.550	**NWithinSpec**	N/A
Mean	1.515	**NOutsideSpec**	N/A
StdDev	34.198E-03	**90%**	1.550
25%	1.500	**Range**	150.001E-03
Mean+3*StdDev	1.618	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.413	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.0945		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

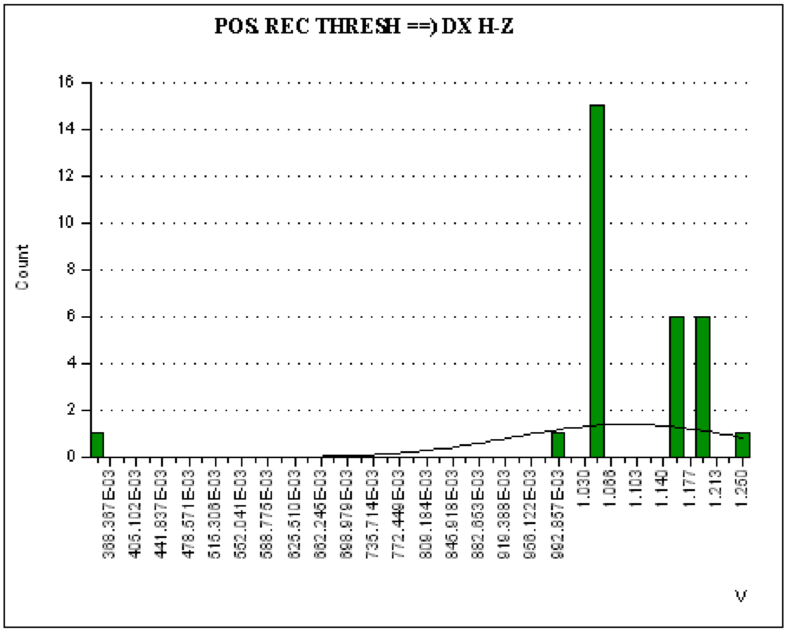
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.007, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

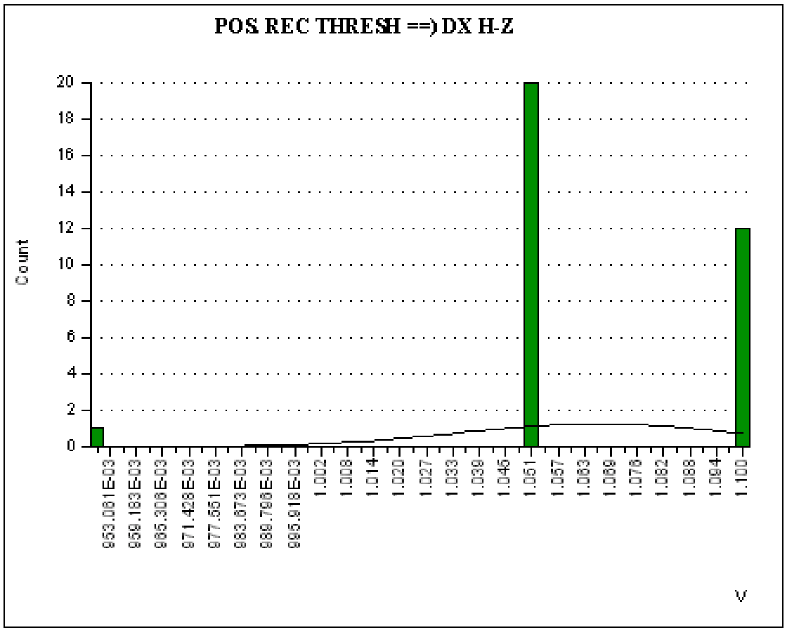
Min	350.000E-03	**Skew**	-3.7257
Max	1.250	**StatHigh**	N/A
Mean	1.082	**StatLow**	N/A
StdDev	155.077E-03	**NWithinSpec**	N/A
25%	1.050	**NOutsideSpec**	N/A
Mean+3*StdDev	1.547	**90%**	1.200
		Range	900.000E-03
Mean-3*StdDev	616.436E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.007, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.100	**NWithinSpec**	N/A
Mean	1.065	**NOutsideSpec**	N/A
StdDev	31.831E-03	**90%**	1.100
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.161	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	969.657E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.1228		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

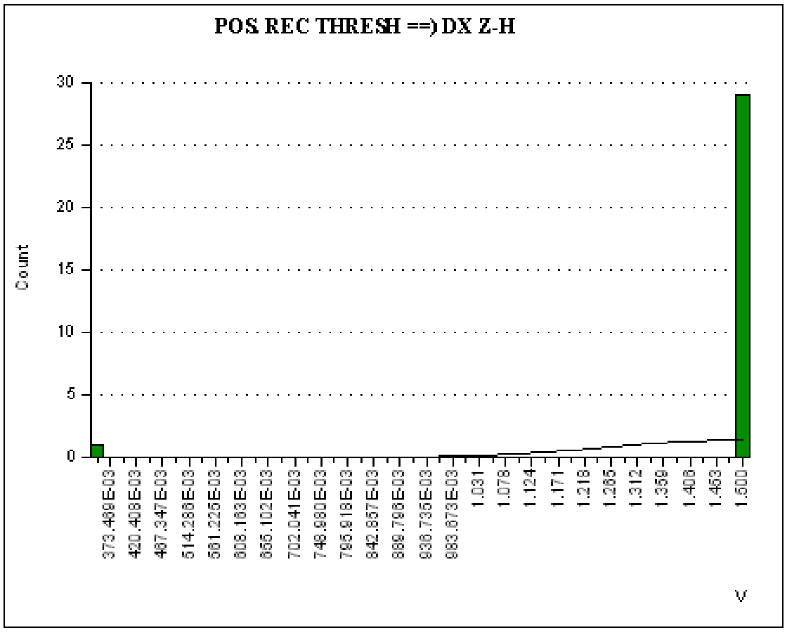
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.008, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

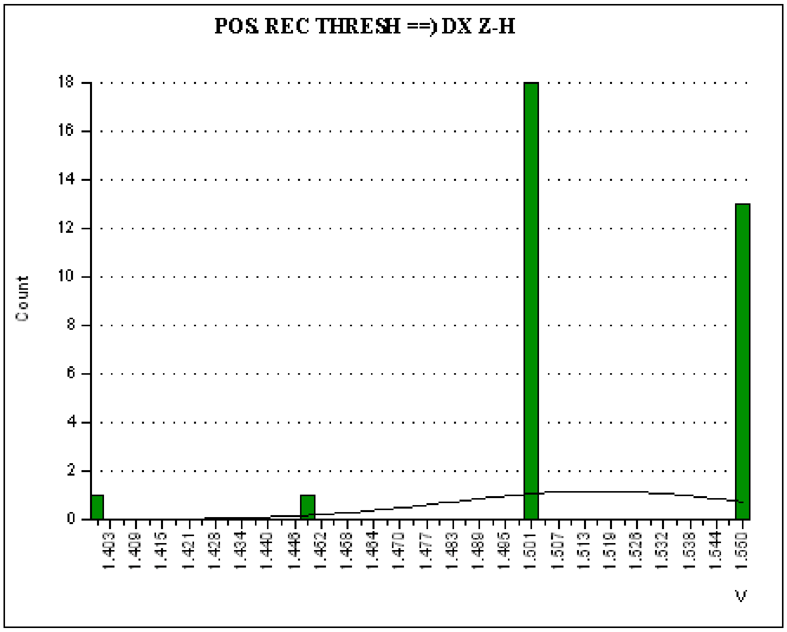
Min	350.000E-03	**Skew**	-5.4772
Max	1.500	**StatHigh**	N/A
Mean	1.462	**StatLow**	N/A
StdDev	209.960E-03	**NWithinSpec**	N/A
25%	1.500	**NOutsideSpec**	N/A
Mean+3*StdDev	2.092	**90%**	1.500
		Range	1.150
Mean-3*StdDev	831.786E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.008, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.400	**StatLow**	N/A
Max	1.550	**NWithinSpec**	N/A
Mean	1.515	**NOutsideSpec**	N/A
StdDev	34.198E-03	**90%**	1.550
25%	1.500	**Range**	150.001E-03
Mean+3*StdDev	1.618	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.413	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-1.0945		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

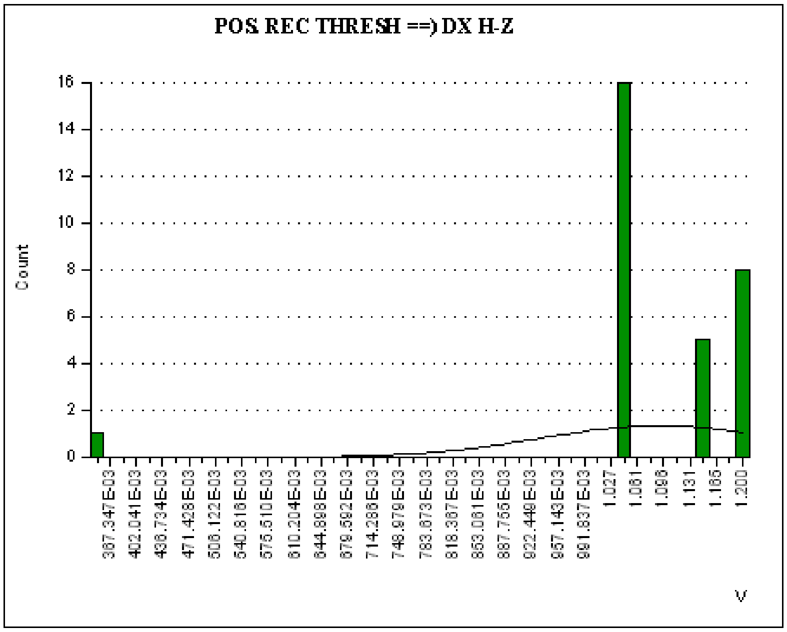
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.009, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

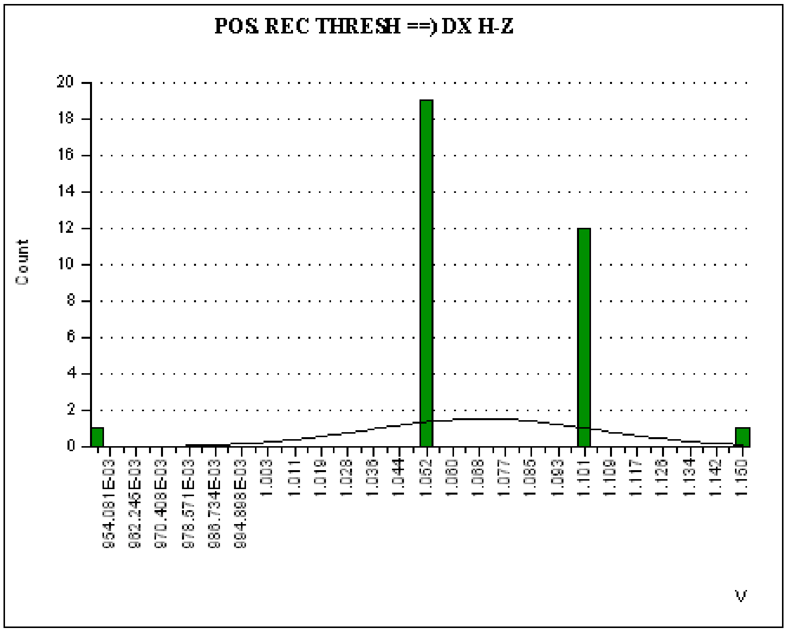
Min	350.000E-03	**Skew**	-3.8611
Max	1.200	**StatHigh**	N/A
Mean	1.083	**StatLow**	N/A
StdDev	153.877E-03	**NWithinSpec**	N/A
25%	1.050	**NOutsideSpec**	N/A
Mean+3*StdDev	1.545	**90%**	1.200
		Range	850.000E-03
Mean-3*StdDev	621.702E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.009, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.150	**NWithinSpec**	N/A
Mean	1.068	**NOutsideSpec**	N/A
StdDev	34.951E-03	**90%**	1.100
25%	1.050	**Range**	200.000E-03
Mean+3*StdDev	1.173	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	963.329E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.6472		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

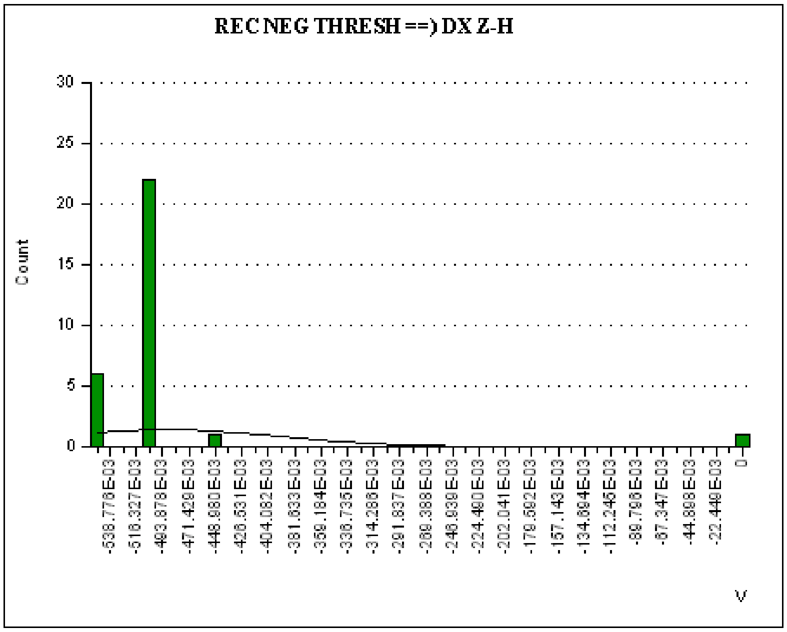
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.010, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

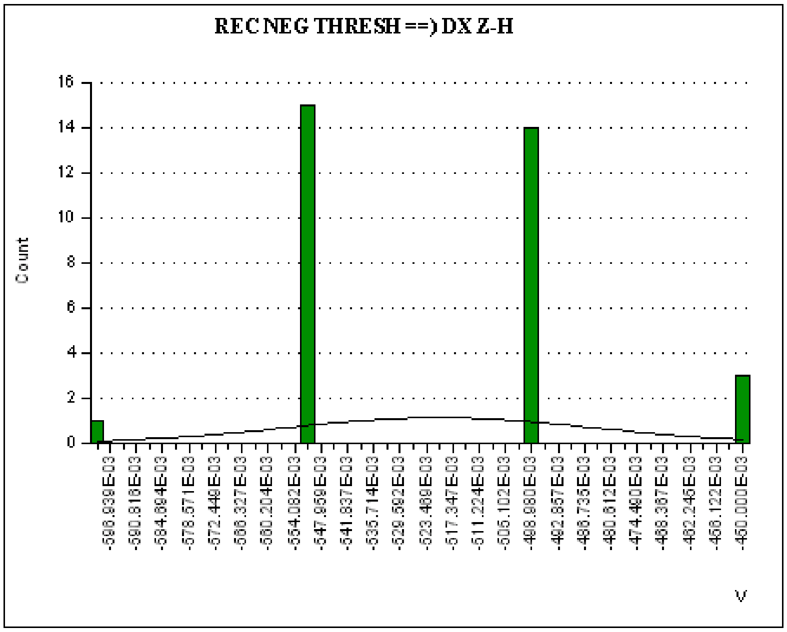
Min	-550.000E-03	**Skew**	4.9674
Max	0	**StatHigh**	N/A
Mean	-491.667E-03	**StatLow**	N/A
StdDev	95.668E-03	**NWithinSpec**	N/A
25%	-500.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-204.664E-03	**90%**	-500.000E-03
		Range	550.000E-03
Mean-3*StdDev	-778.670E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.010, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-450.000E-03	**NWithinSpec**	N/A
Mean	-521.212E-03	**NOutsideSpec**	N/A
StdDev	35.422E-03	**90%**	-500.000E-03
25%	-550.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-414.945E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-627.479E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2770		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

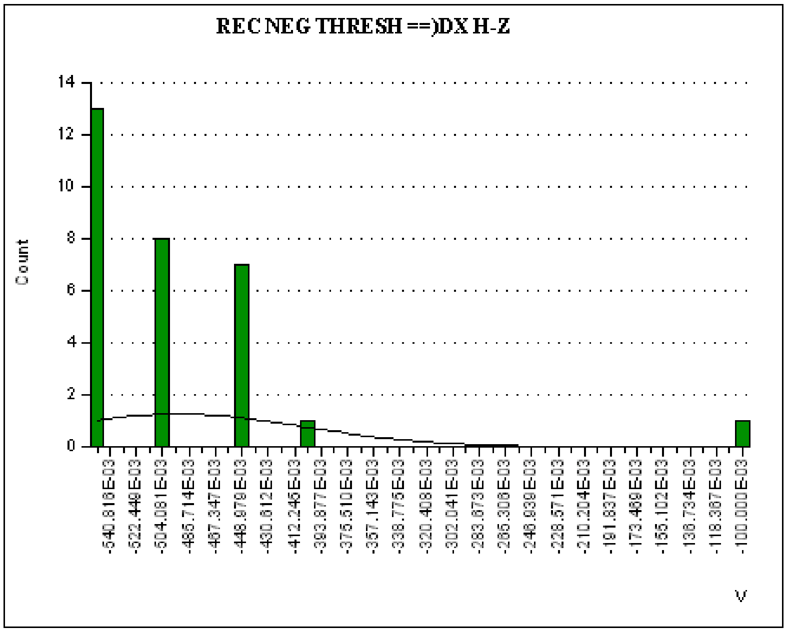
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.011, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

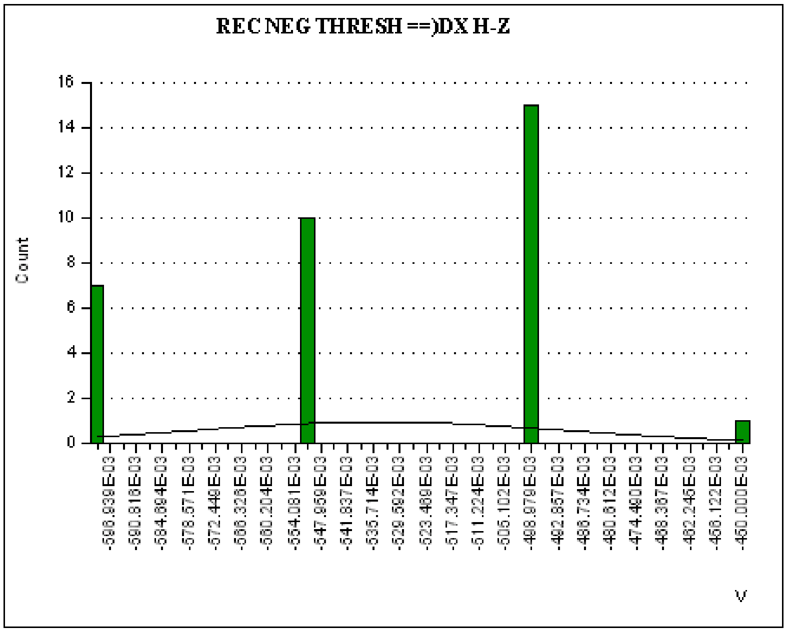
Min	-550.000E-03	**Skew**	3.3782
Max	-100.000E-03	**StatHigh**	N/A
Mean	-493.333E-03	**StatLow**	N/A
StdDev	86.834E-03	**NWithinSpec**	N/A
25%	-550.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-232.830E-03	**90%**	-450.000E-03
		Range	450.000E-03
Mean-3*StdDev	-753.837E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.011, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-450.000E-03	**NWithinSpec**	N/A
Mean	-534.848E-03	**NOutsideSpec**	N/A
StdDev	42.362E-03	**90%**	-500.000E-03
25%	-550.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-407.763E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-661.933E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.3173		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

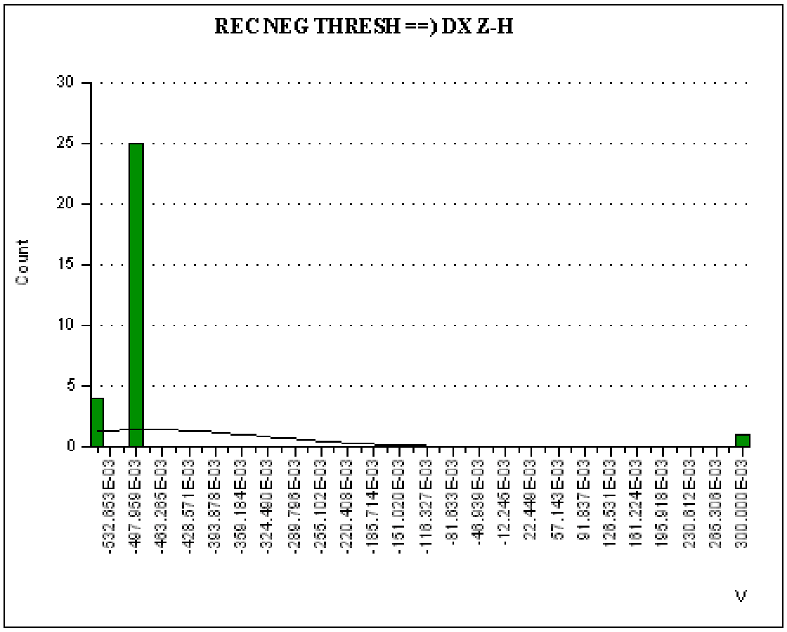
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.012, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

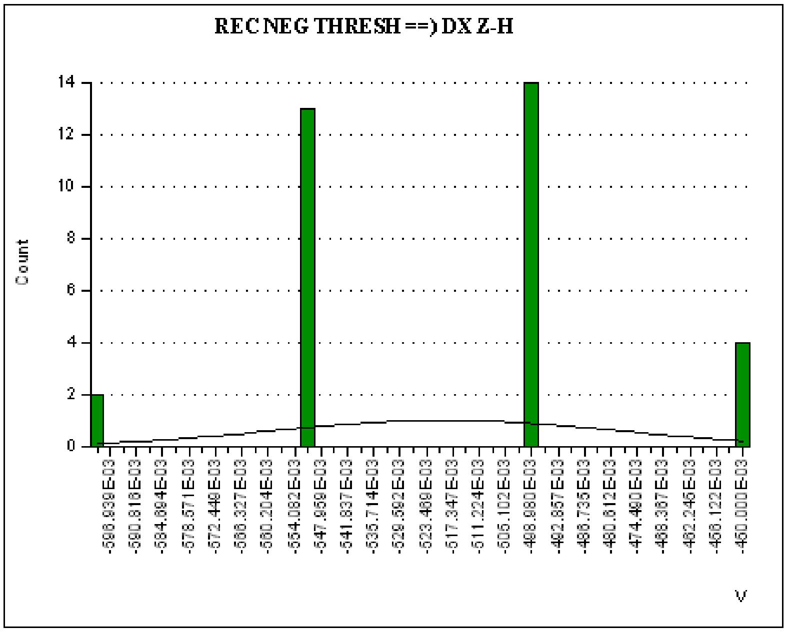
Min	-550.000E-03	**Skew**	5.3552
Max	300.000E-03	**StatHigh**	N/A
Mean	-480.000E-03	**StatLow**	N/A
StdDev	148.324E-03	**NWithinSpec**	N/A
25%	-500.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-35.028E-03	**90%**	-500.000E-03
		Range	850.000E-03
Mean-3*StdDev	-924.972E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.012, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-450.000E-03	**NWithinSpec**	N/A
Mean	-519.697E-03	**NOutsideSpec**	N/A
StdDev	39.409E-03	**90%**	-450.000E-03
25%	-550.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-401.471E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-637.923E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0347		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

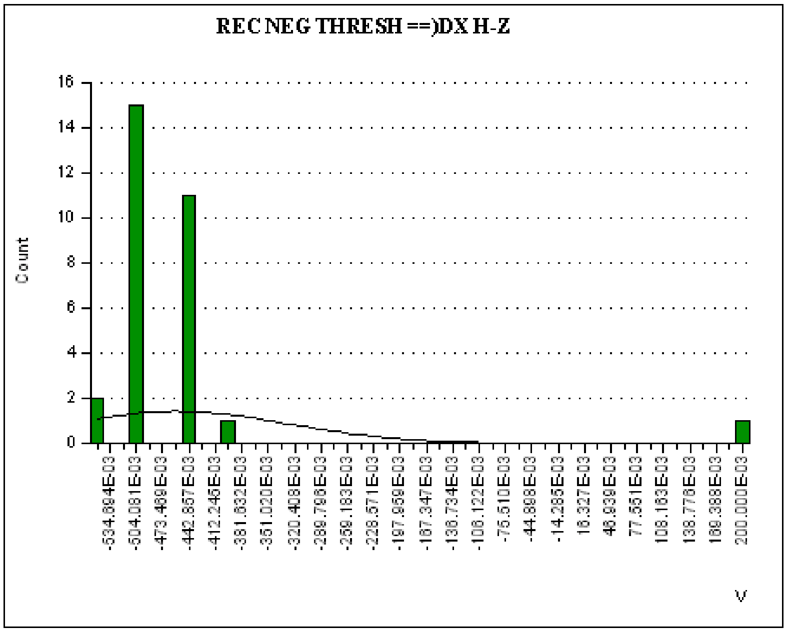
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.013, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

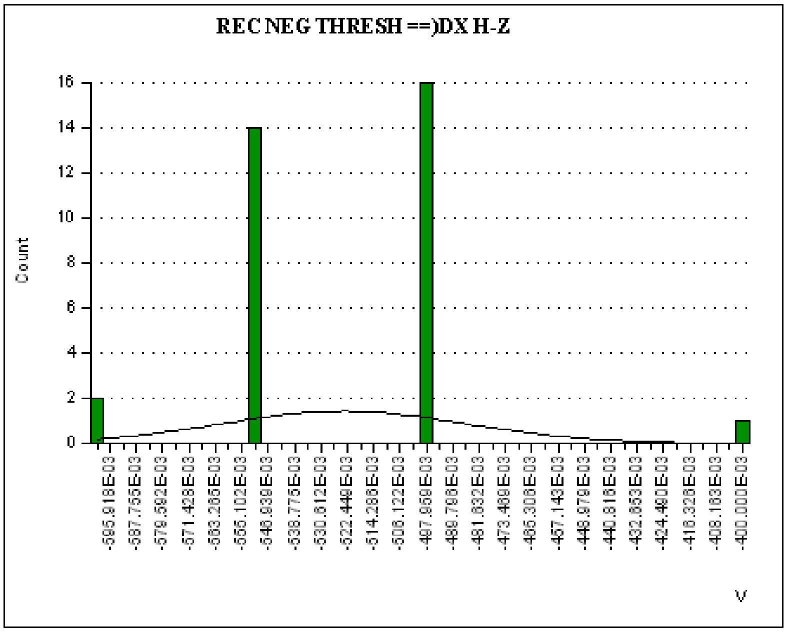
Min	-550.000E-03	**Skew**	4.9020
Max	200.000E-03	**StatHigh**	N/A
Mean	-458.333E-03	**StatLow**	N/A
StdDev	128.709E-03	**NWithinSpec**	N/A
25%	-500.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-72.205E-03	**90%**	-450.000E-03
		Range	750.000E-03
Mean-3*StdDev	-844.461E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.013, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-400.000E-03	**NWithinSpec**	N/A
Mean	-524.242E-03	**NOutsideSpec**	N/A
StdDev	37.752E-03	**90%**	-500.000E-03
25%	-550.000E-03	**Range**	200.000E-03
Mean+3*StdDev	-410.987E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-637.497E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.6411		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

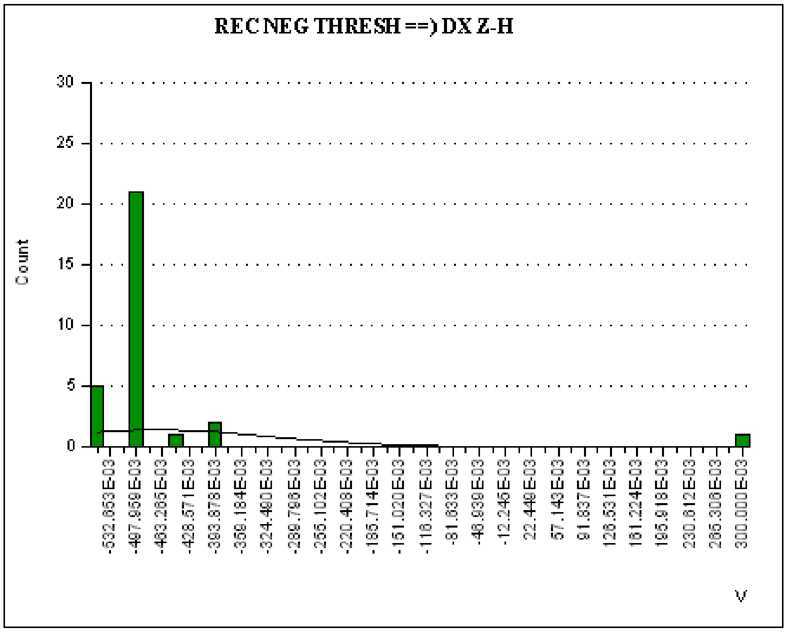
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.014, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

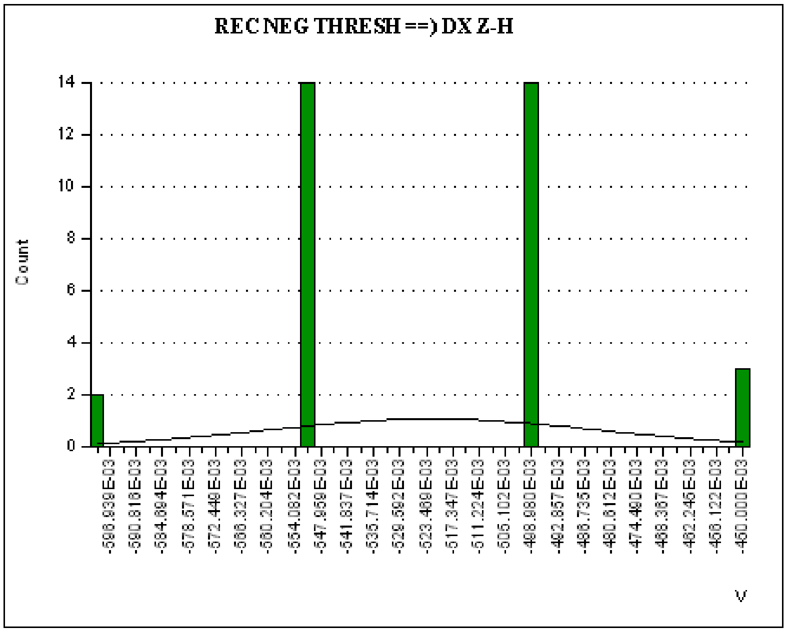
Min	-550.000E-03	**Skew**	5.0291
Max	300.000E-03	**StatHigh**	N/A
Mean	-473.333E-03	**StatLow**	N/A
StdDev	150.134E-03	**NWithinSpec**	N/A
25%	-500.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-22.931E-03	**90%**	-425.000E-03
		Range	850.000E-03
Mean-3*StdDev	-923.735E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.014, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-450.000E-03	**NWithinSpec**	N/A
Mean	-522.727E-03	**NOutsideSpec**	N/A
StdDev	37.689E-03	**90%**	-500.000E-03
25%	-550.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-409.660E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-635.794E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0693		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

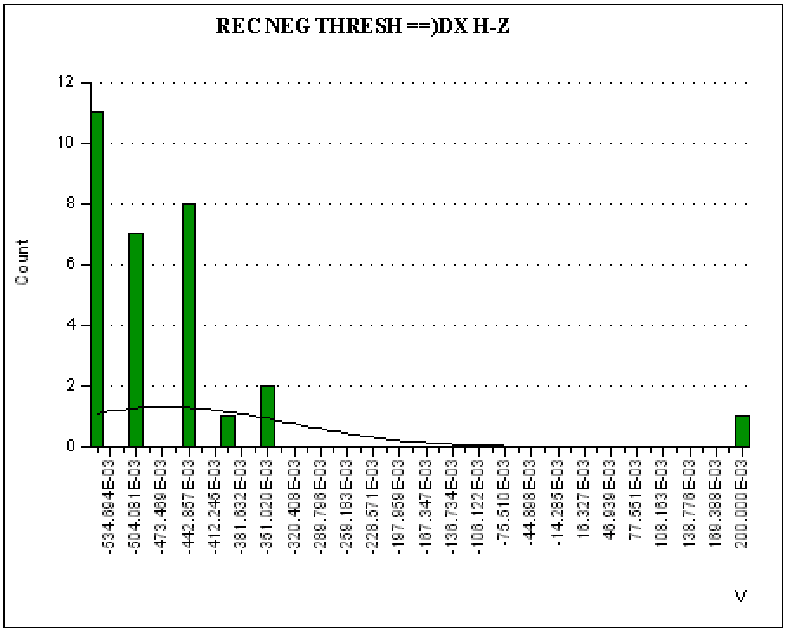
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.015, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

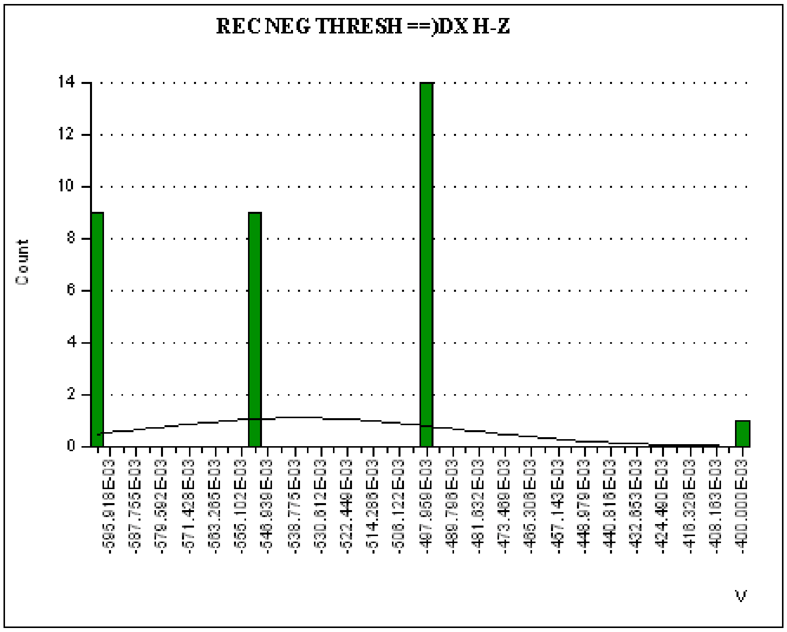
Min	-550.000E-03	**Skew**	4.0491
Max	200.000E-03	**StatHigh**	N/A
Mean	-468.333E-03	**StatLow**	N/A
StdDev	139.261E-03	**NWithinSpec**	N/A
25%	-550.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-50.550E-03	**90%**	-375.000E-03
		Range	750.000E-03
Mean-3*StdDev	-886.117E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.015, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-400.000E-03	**NWithinSpec**	N/A
Mean	-537.879E-03	**NOutsideSpec**	N/A
StdDev	48.461E-03	**90%**	-500.000E-03
25%	-600.000E-03	**Range**	200.000E-03
Mean+3*StdDev	-392.495E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-683.262E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3532		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

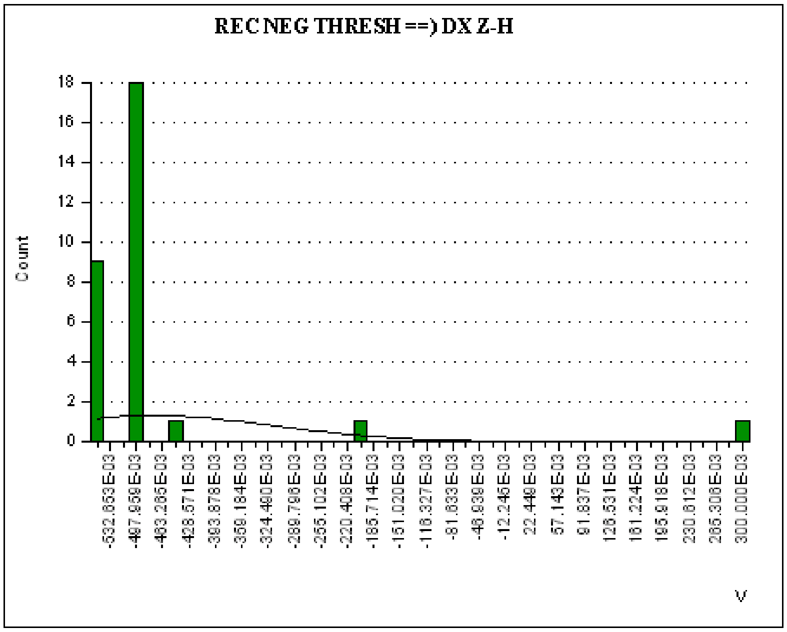
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.016, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

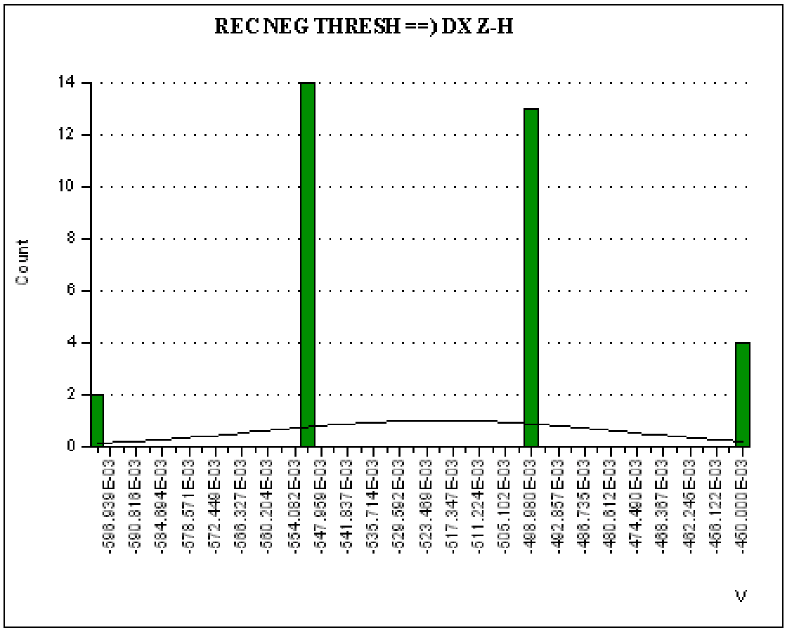
Min	-550.000E-03	**Skew**	4.4162
Max	300.000E-03	**StatHigh**	N/A
Mean	-476.667E-03	**StatLow**	N/A
StdDev	159.597E-03	**NWithinSpec**	N/A
25%	-550.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	2.125E-03	**90%**	-475.000E-03
		Range	850.000E-03
Mean-3*StdDev	-955.458E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.016, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-450.000E-03	**NWithinSpec**	N/A
Mean	-521.212E-03	**NOutsideSpec**	N/A
StdDev	39.588E-03	**90%**	-450.000E-03
25%	-550.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-402.447E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-639.977E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.1375		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

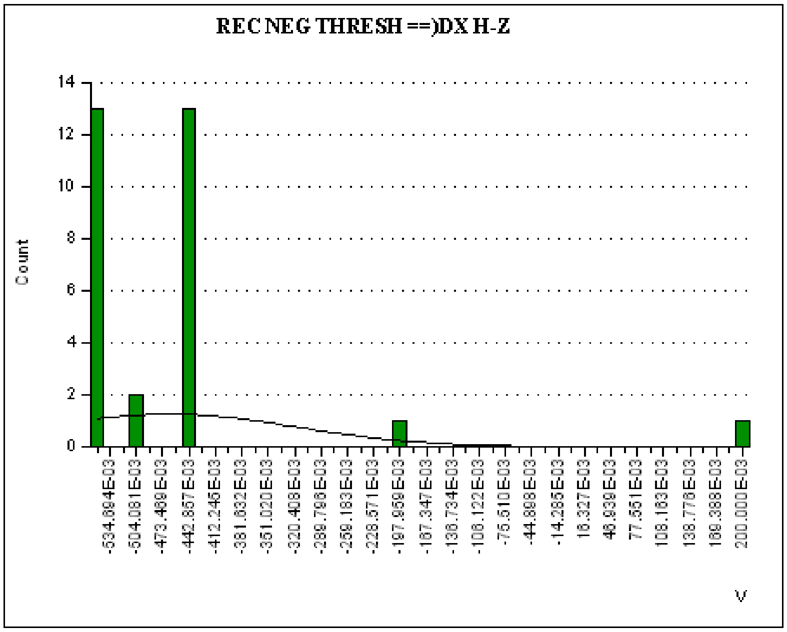
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.017, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

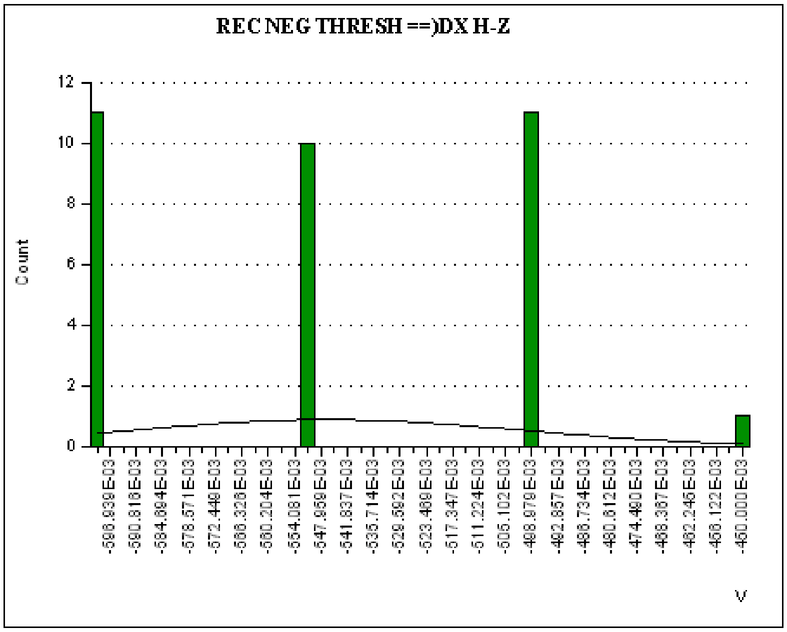
Min	-550.000E-03	**Skew**	3.7115
Max	200.000E-03	**StatHigh**	N/A
Mean	-466.666E-03	**StatLow**	N/A
StdDev	145.231E-03	**NWithinSpec**	N/A
25%	-550.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-30.974E-03	**90%**	-450.000E-03
		Range	750.000E-03
Mean-3*StdDev	-902.359E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.017, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-450.000E-03	**NWithinSpec**	N/A
Mean	-546.969E-03	**NOutsideSpec**	N/A
StdDev	44.964E-03	**90%**	-500.000E-03
25%	-600.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-412.077E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-681.862E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.1504		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

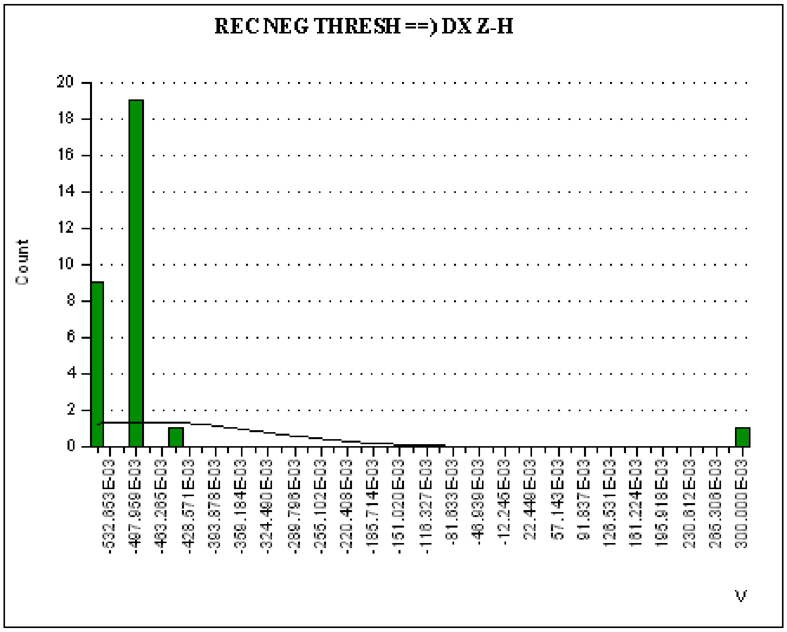
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.018, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

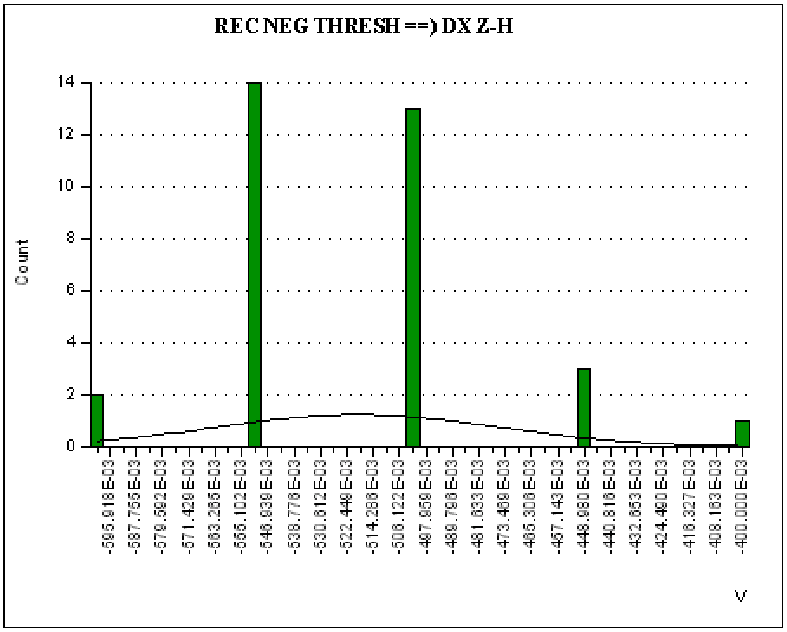
Min	-550.000E-03	**Skew**	5.2180
Max	300.000E-03	**StatHigh**	N/A
Mean	-486.667E-03	**StatLow**	N/A
StdDev	150.822E-03	**NWithinSpec**	N/A
25%	-550.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-34.202E-03	**90%**	-500.000E-03
		Range	850.000E-03
Mean-3*StdDev	-939.131E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.018, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-400.000E-03	**NWithinSpec**	N/A
Mean	-519.697E-03	**NOutsideSpec**	N/A
StdDev	43.192E-03	**90%**	-450.000E-03
25%	-550.000E-03	**Range**	200.000E-03
Mean+3*StdDev	-390.122E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-649.272E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.5800		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

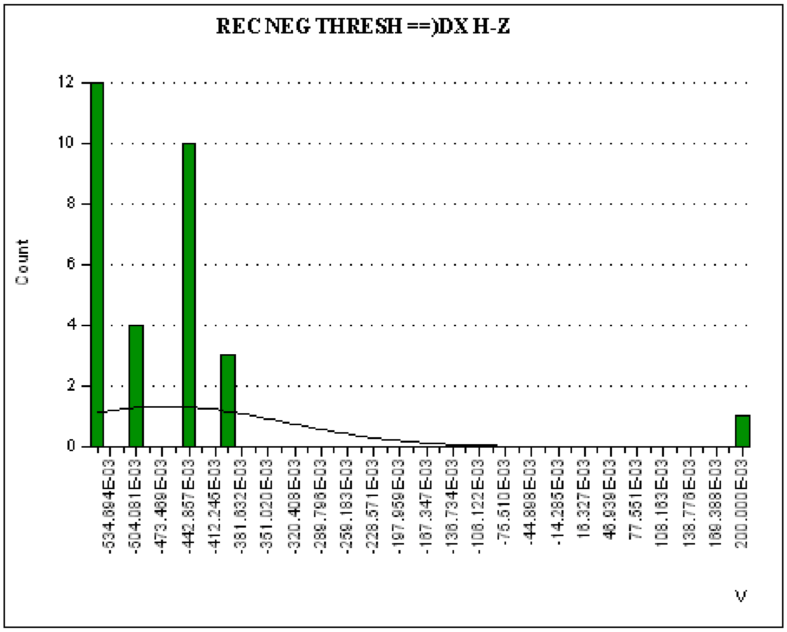
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=13.019, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

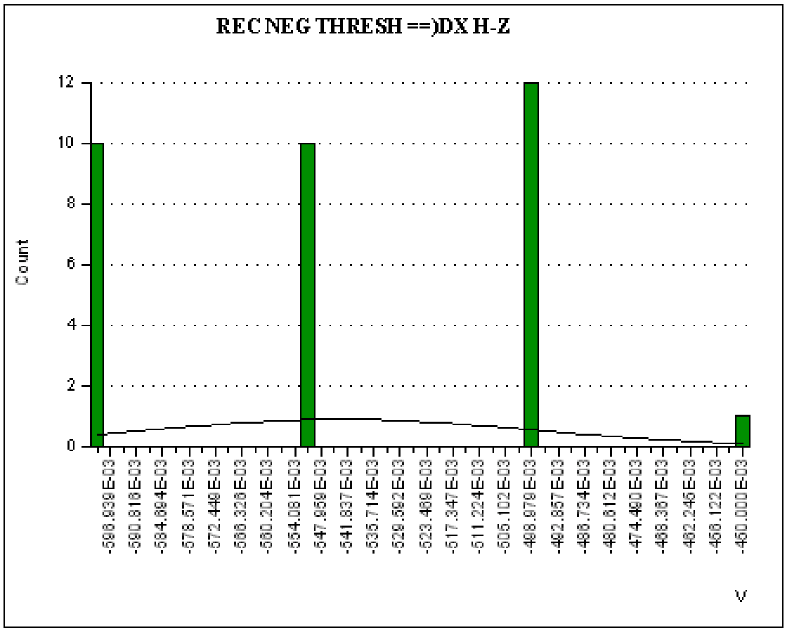
Min	-550.000E-03	**Skew**	4.2046
Max	200.000E-03	**StatHigh**	N/A
Mean	-470.000E-03	**StatLow**	N/A
StdDev	137.465E-03	**NWithinSpec**	N/A
25%	-550.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-57.606E-03	**90%**	-400.000E-03
		Range	750.000E-03
Mean-3*StdDev	-882.394E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.019, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-600.000E-03	**StatLow**	N/A
Max	-450.000E-03	**NWithinSpec**	N/A
Mean	-543.939E-03	**NOutsideSpec**	N/A
StdDev	44.647E-03	**90%**	-500.000E-03
25%	-600.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-409.998E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-677.881E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0310		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

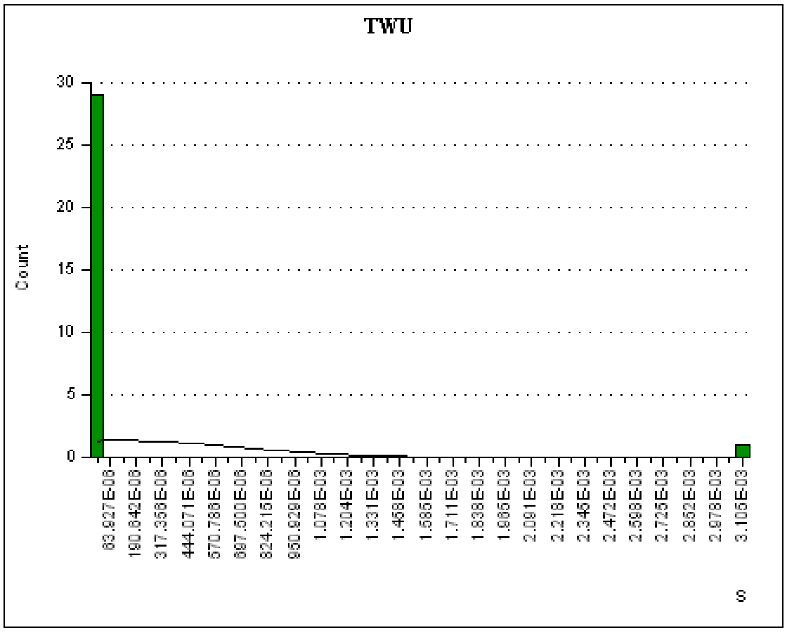
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=14.000, Test.Name=TWU



Statistics: (S)

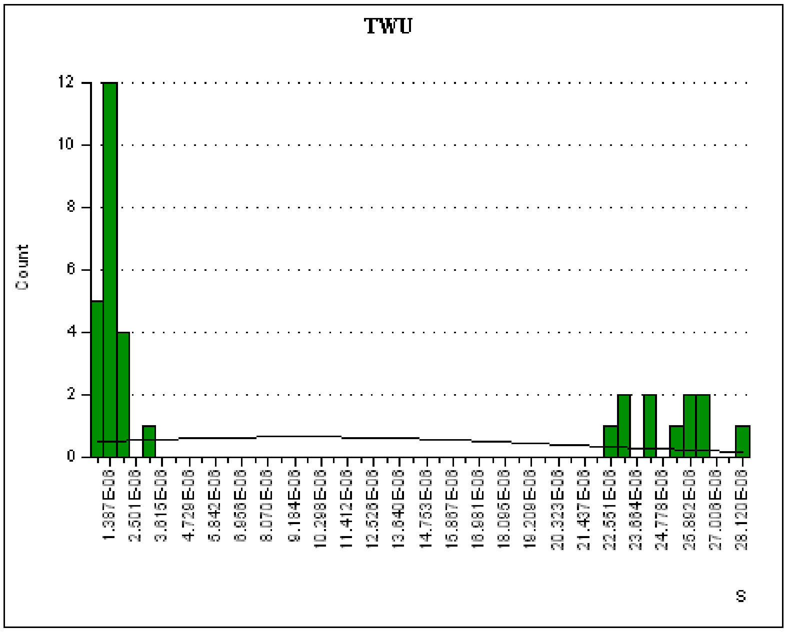
Min	569.999E-09	**Skew**	5.4768
Max	3.105E-03	**StatHigh**	N/A
Mean	105.322E-06	**StatLow**	N/A
StdDev	566.578E-06	**NWithinSpec**	N/A
25%	639.999E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	1.805E-03	**90%**	7.415E-06
		Range	3.105E-03
Mean-3*StdDev	-1.594E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=14.000, Test.Name=TWU



Statistics: (S)

Min	829.999E-09	**StatLow**	N/A
Max	28.120E-06	**NWithinSpec**	N/A
Mean	9.291E-06	**NOutsideSpec**	N/A
StdDev	11.330E-06	**90%**	26.100E-06
25%	1.210E-06	**Range**	27.290E-06
Mean+3*StdDev	43.281E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-24.698E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.7635		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

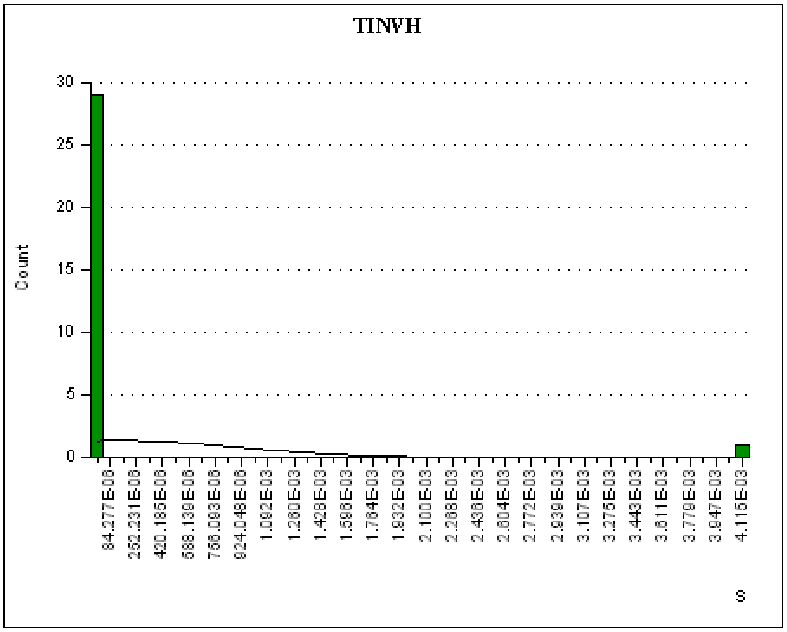
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=15.000, Test.Name=TINVH



Statistics: (S)

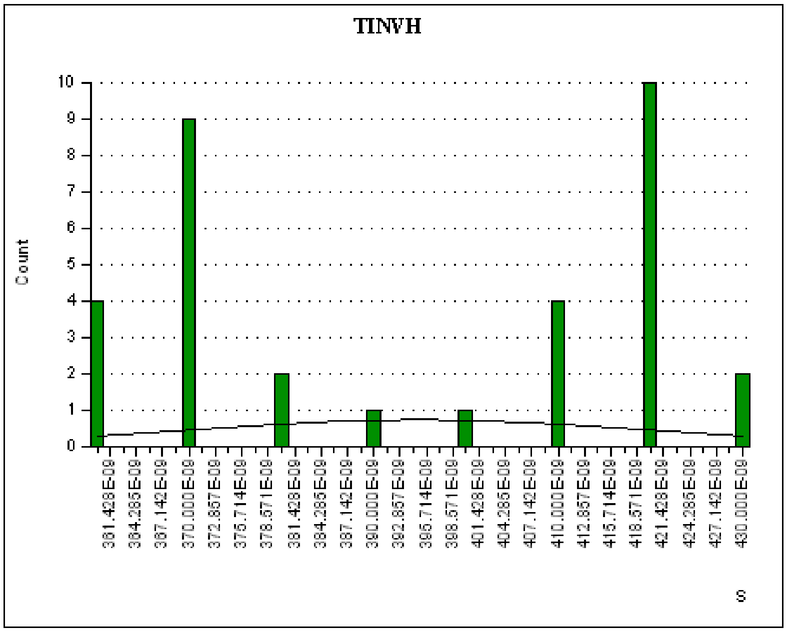
Min	300.000E-09	**Skew**	5.4772
Max	4.115E-03	**StatHigh**	N/A
Mean	137.479E-06	**StatLow**	N/A
StdDev	751.267E-06	**NWithinSpec**	N/A
25%	310.000E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	2.391E-03	**90%**	335.000E-09
		Range	4.115E-03
Mean-3*StdDev	-2.116E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=15.000, Test.Name=TINVH



Statistics: (S)

Min	360.000E-09	**StatLow**	N/A
Max	430.000E-09	**NWithinSpec**	N/A
Mean	394.545E-09	**NOutsideSpec**	N/A
StdDev	25.383E-09	**90%**	420.000E-09
25%	370.000E-09	**Range**	70.000E-09
Mean+3*StdDev	470.695E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	318.395E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0717		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

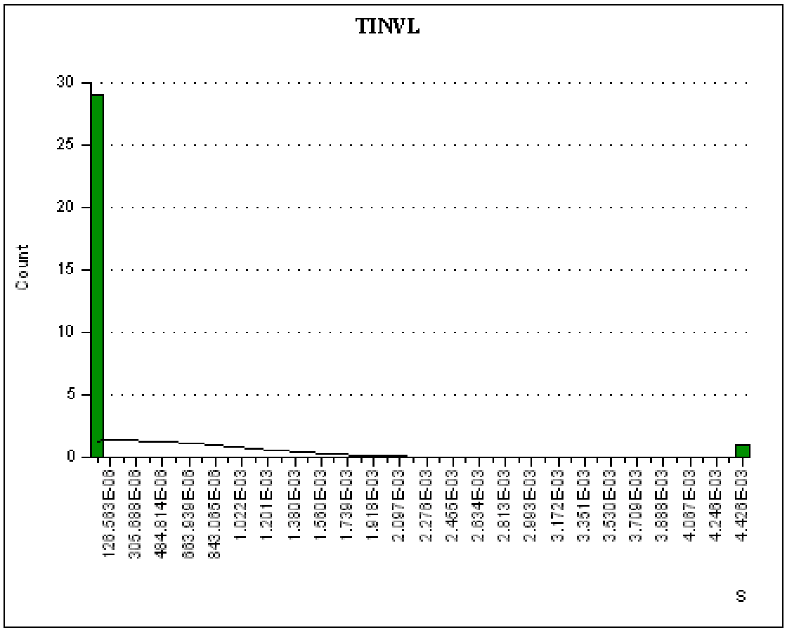
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=15.001, Test.Name=TINVL



Statistics: (S)

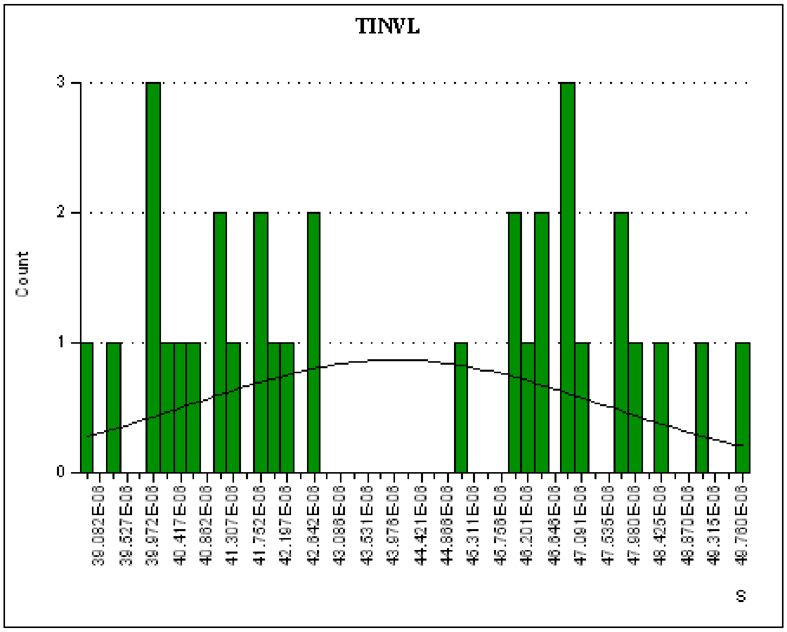
Min	37.000E-06	**Skew**	5.4772
Max	4.426E-03	**StatHigh**	N/A
Mean	185.688E-06	**StatLow**	N/A
StdDev	800.787E-06	**NWithinSpec**	N/A
25%	38.610E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	2.588E-03	**90%**	40.735E-06
		Range	4.389E-03
Mean-3*StdDev	-2.217E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=15.001, Test.Name=TINVL



Statistics: (S)

Min	38.860E-06	**StatLow**	N/A
Max	49.760E-06	**NWithinSpec**	N/A
Mean	43.952E-06	**NOutsideSpec**	N/A
StdDev	3.369E-06	**90%**	48.060E-06
25%	41.140E-06	**Range**	10.900E-06
Mean+3*StdDev	54.058E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	33.845E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0933		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

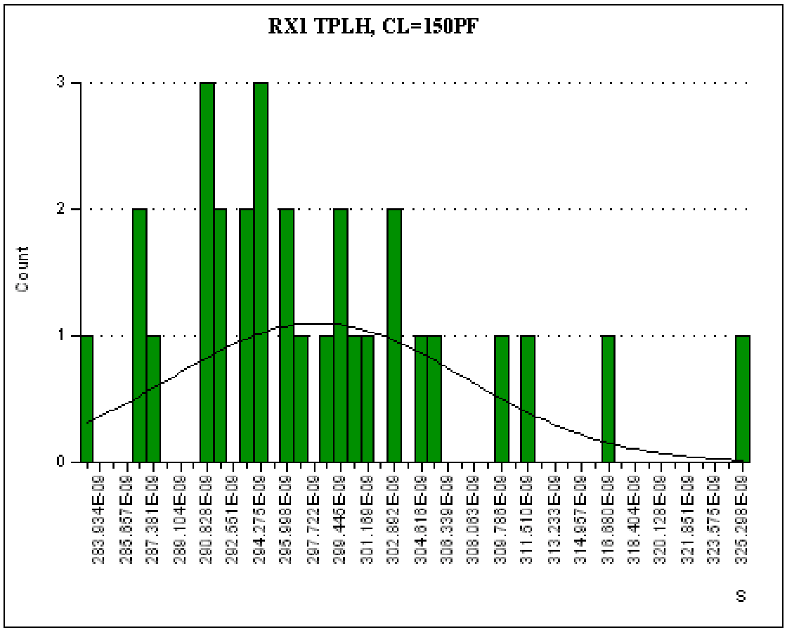
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.000, Test.Name=RX1 TPLH, CL=150PF



Statistics: (S)

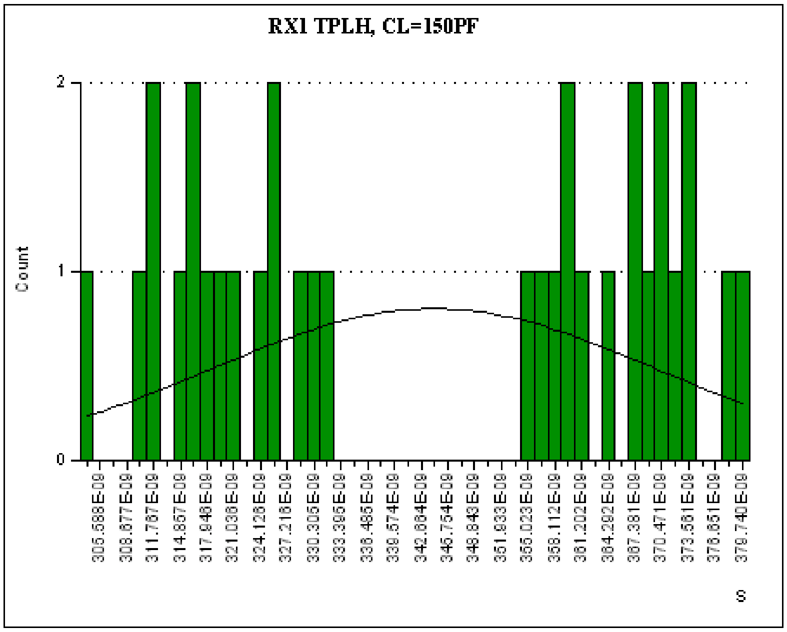
Min	283.072E-09	**Skew**	1.0821
Max	325.298E-09	**StatHigh**	N/A
Mean	297.820E-09	**StatLow**	N/A
StdDev	9.361E-09	**NWithinSpec**	N/A
25%	291.334E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	325.904E-09	**90%**	310.611E-09
		Range	42.226E-09
Mean-3*StdDev	269.737E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.000, Test.Name=RX1 TPLH, CL=150PF



Statistics: (S)

Min	304.043E-09	**StatLow**	N/A
Max	379.740E-09	**NWithinSpec**	N/A
Mean	343.746E-09	**NOutsideSpec**	N/A
StdDev	25.270E-09	**90%**	374.133E-09
25%	318.995E-09	**Range**	75.697E-09
Mean+3*StdDev	419.558E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	267.935E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.0709		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

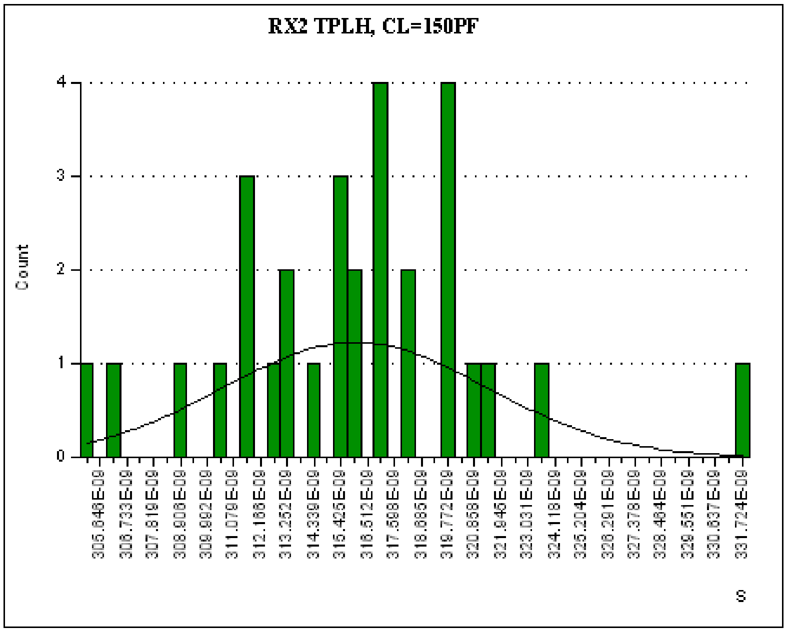
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.001, Test.Name=RX2 TPLH, CL=150PF



Statistics: (S)

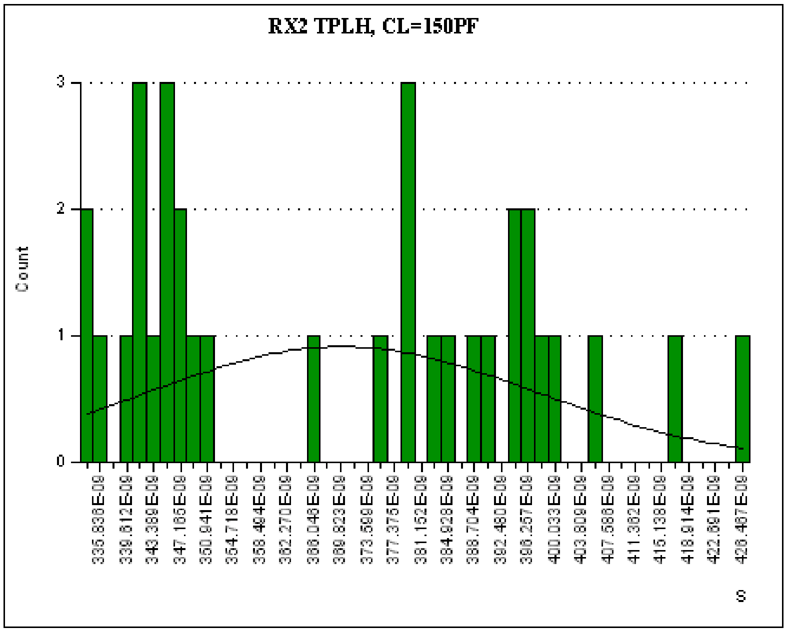
Min	305.103E-09	**Skew**	0.4645
Max	331.724E-09	**StatHigh**	N/A
Mean	315.904E-09	**StatLow**	N/A
StdDev	5.307E-09	**NWithinSpec**	N/A
25%	312.447E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	331.826E-09	**90%**	321.167E-09
		Range	26.621E-09
Mean-3*StdDev	299.983E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.001, Test.Name=RX2 TPLH, CL=150PF



Statistics: (S)

Min	333.948E-09	**StatLow**	N/A
Max	426.467E-09	**NWithinSpec**	N/A
Mean	369.659E-09	**NOutsideSpec**	N/A
StdDev	27.197E-09	**90%**	399.365E-09
25%	345.162E-09	**Range**	92.519E-09
Mean+3*StdDev	451.249E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	288.068E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.2698		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

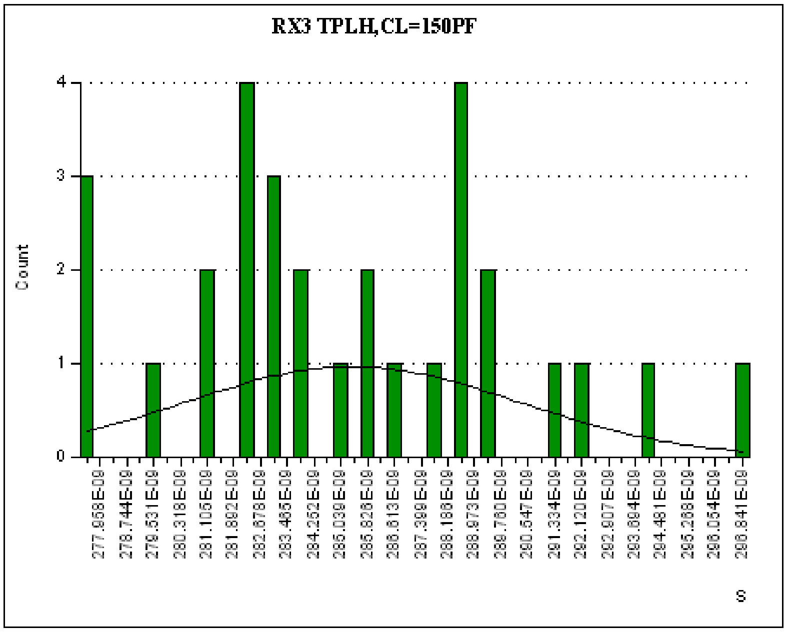
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.002, Test.Name=RX3 TPLH,CL=150PF



Statistics: (S)

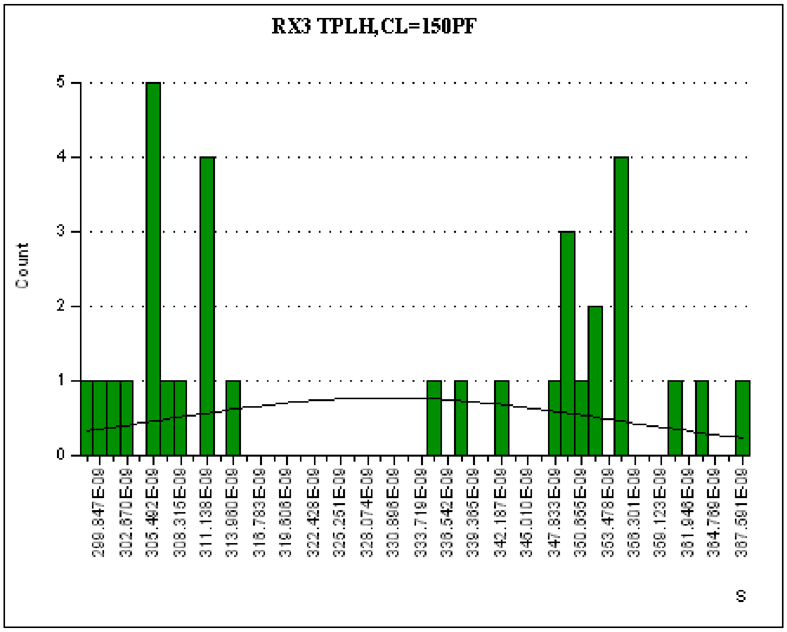
Min	277.564E-09	**Skew**	0.3763
Max	296.841E-09	**StatHigh**	N/A
Mean	285.306E-09	**StatLow**	N/A
StdDev	4.867E-09	**NWithinSpec**	N/A
25%	282.154E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	299.908E-09	**90%**	291.793E-09
		Range	19.277E-09
Mean-3*StdDev	270.703E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.002, Test.Name=RX3 TPLH,CL=150PF



Statistics: (S)

Min	298.436E-09	**StatLow**	N/A
Max	367.591E-09	**NWithinSpec**	N/A
Mean	329.813E-09	**NOutsideSpec**	N/A
StdDev	23.994E-09	**90%**	355.442E-09
25%	305.912E-09	**Range**	69.156E-09
Mean+3*StdDev	401.795E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	257.832E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0576		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

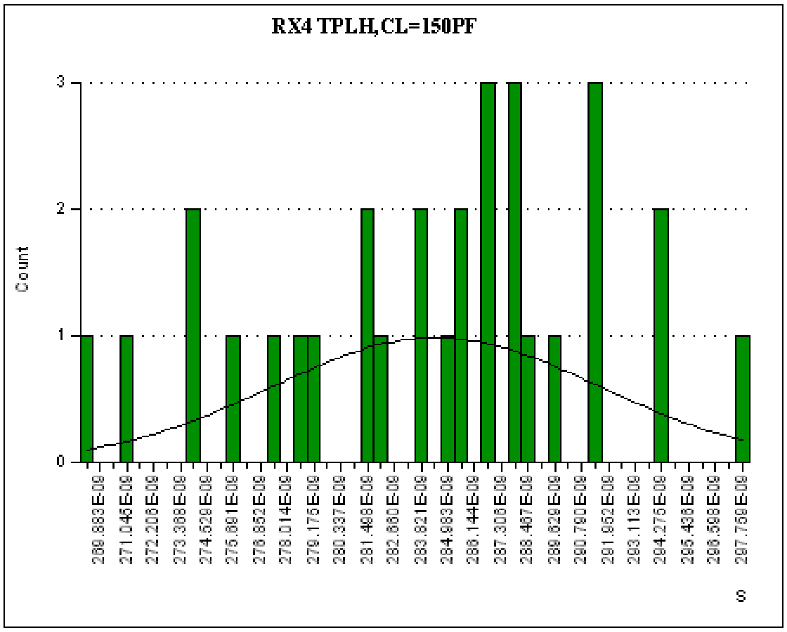
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.003, Test.Name=RX4 TPLH,CL=150PF



Statistics: (S)

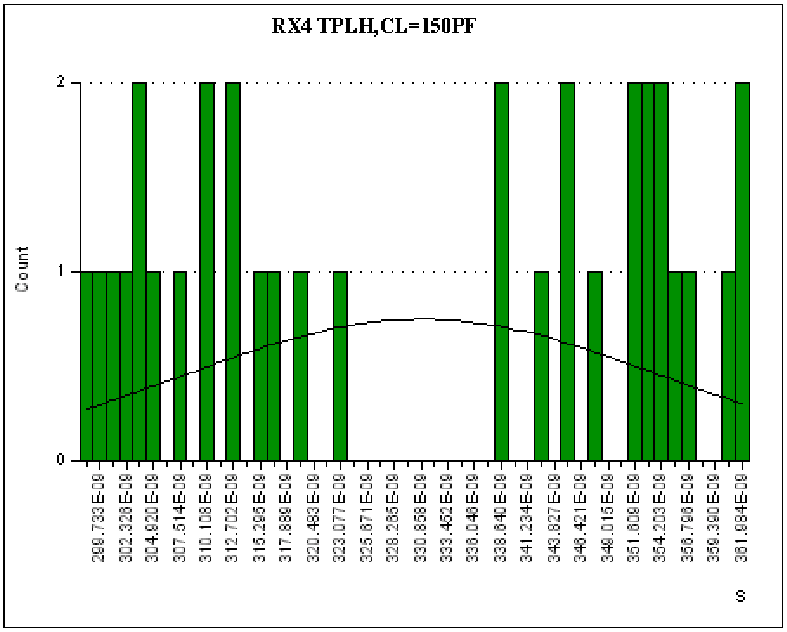
Min	269.303E-09	**Skew**	-0.3806
Max	297.759E-09	**StatHigh**	N/A
Mean	284.326E-09	**StatLow**	N/A
StdDev	7.043E-09	**NWithinSpec**	N/A
25%	279.400E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	305.454E-09	**90%**	292.710E-09
		Range	28.457E-09
Mean-3*StdDev	263.198E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.003, Test.Name=RX4 TPLH,CL=150PF



Statistics: (S)

Min	298.436E-09	**StatLow**	N/A
Max	361.984E-09	**NWithinSpec**	N/A
Mean	330.663E-09	**NOutsideSpec**	N/A
StdDev	22.815E-09	**90%**	356.377E-09
25%	309.650E-09	**Range**	63.548E-09
Mean+3*StdDev	399.108E-09	**NOutsideSpec**	N/A
Mean-3*StdDev	262.218E-09	**Cp**	N/A
Cpk	N/A	**Cpl**	N/A
Skew	-0.0507	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

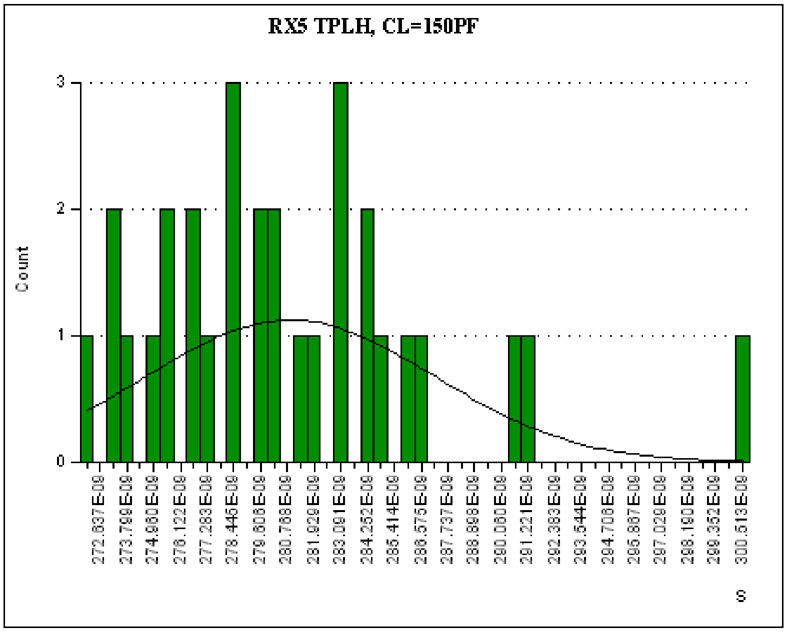
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.004, Test.Name=RX5 TPLH, CL=150PF



Statistics: (S)

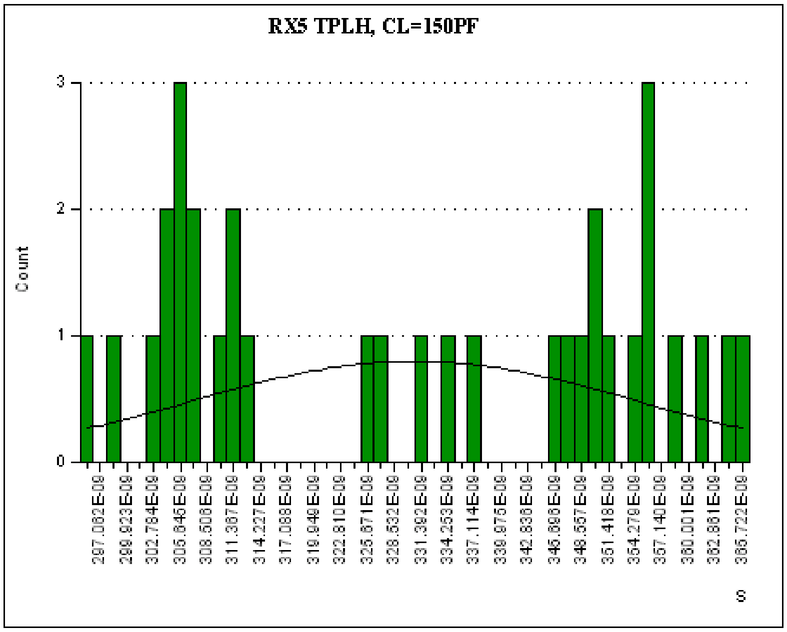
Min	272.056E-09	**Skew**	1.1830
Max	300.513E-09	**StatHigh**	N/A
Mean	280.808E-09	**StatLow**	N/A
StdDev	6.178E-09	**NWithinSpec**	N/A
25%	276.646E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	299.341E-09	**90%**	288.580E-09
		Range	28.457E-09
Mean-3*StdDev	262.274E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.004, Test.Name=RX5 TPLH, CL=150PF



Statistics: (S)

Min	295.632E-09	**StatLow**	N/A
Max	365.722E-09	**NWithinSpec**	N/A
Mean	330.323E-09	**NOutsideSpec**	N/A
StdDev	23.503E-09	**90%**	358.246E-09
25%	306.846E-09	**Range**	70.090E-09
Mean+3*StdDev	400.832E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	259.815E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0175		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

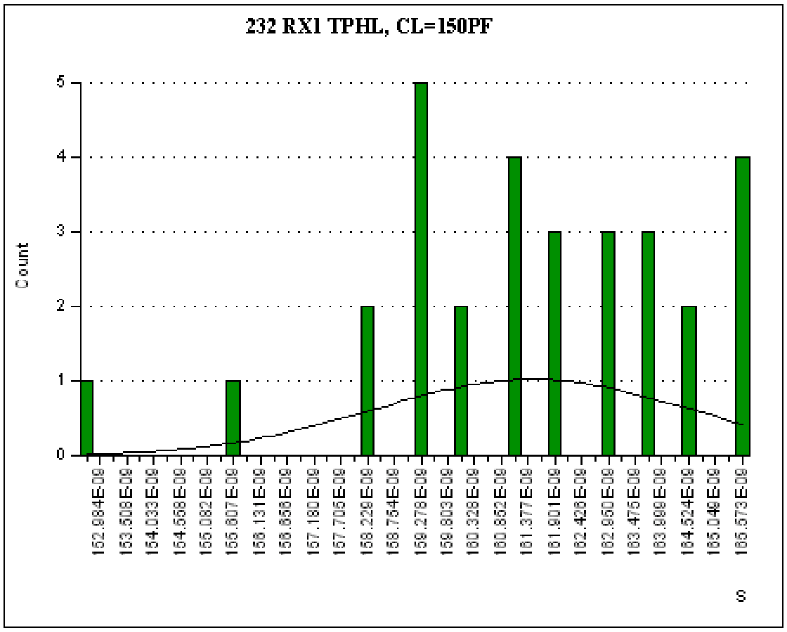
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.005, Test.Name=232 RX1 TPHL, CL=150PF



Statistics: (S)

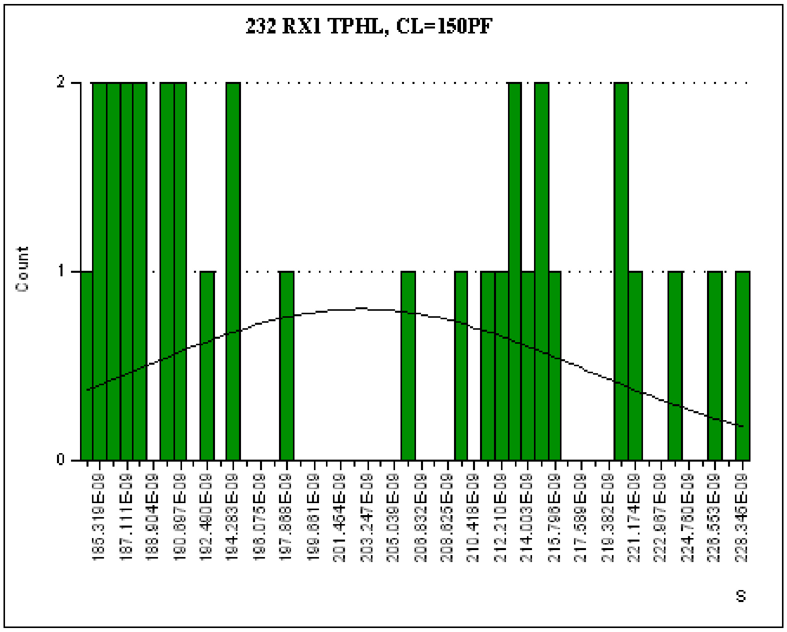
Min	152.722E-09	**Skew**	-0.7181
Max	165.573E-09	**StatHigh**	N/A
Mean	161.381E-09	**StatLow**	N/A
StdDev	3.075E-09	**NWithinSpec**	N/A
25%	159.147E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	170.605E-09	**90%**	165.573E-09
		Range	12.851E-09
Mean-3*StdDev	152.157E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.005, Test.Name=232 RX1 TPHL, CL=150PF



Statistics: (S)

Min	184.422E-09	**StatLow**	N/A
Max	228.345E-09	**NWithinSpec**	N/A
Mean	202.632E-09	**NOutsideSpec**	N/A
StdDev	14.689E-09	**90%**	220.869E-09
25%	188.160E-09	**Range**	43.923E-09
Mean+3*StdDev	246.700E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	158.563E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2231		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

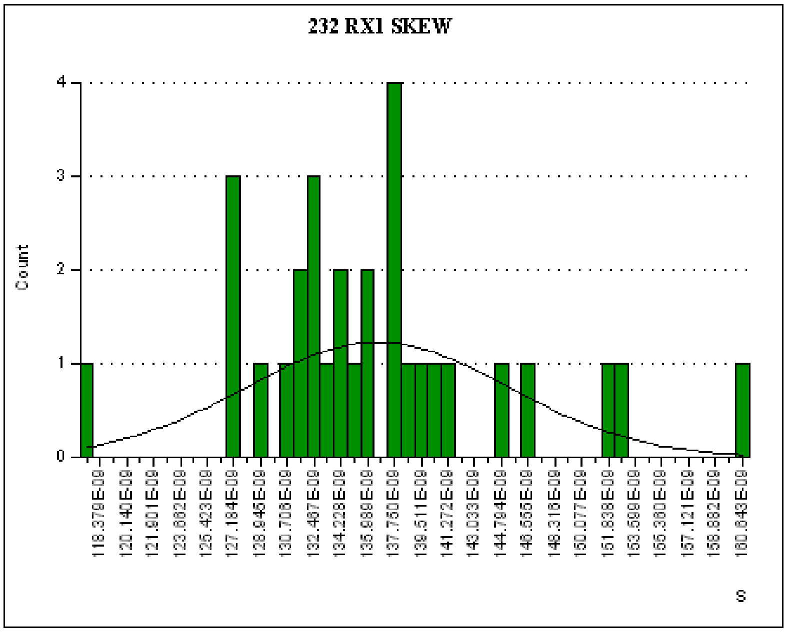
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.006, Test.Name=232 RX1 SKEW



Statistics: (S)

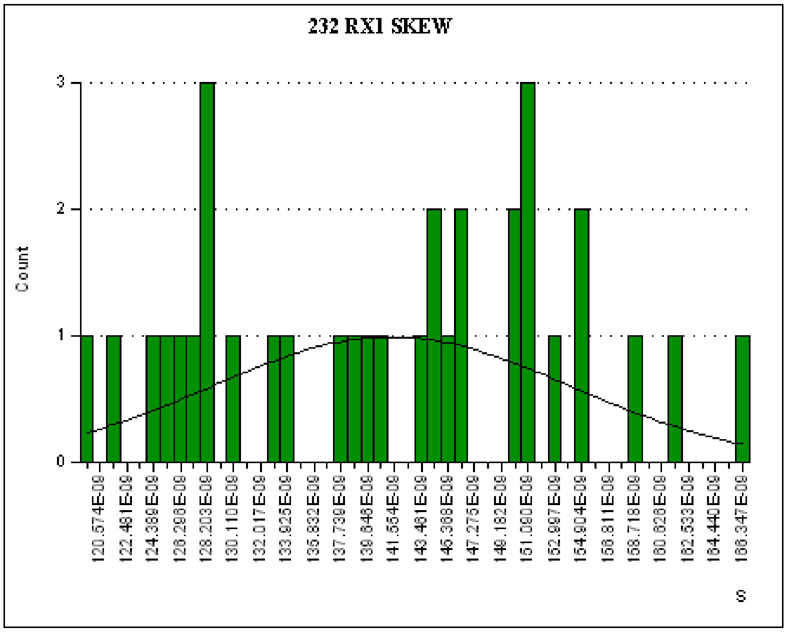
Min	117.499E-09	**Skew**	0.7864
Max	160.643E-09	**StatHigh**	N/A
Mean	136.439E-09	**StatLow**	N/A
StdDev	8.582E-09	**NWithinSpec**	N/A
25%	131.268E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	162.187E-09	**90%**	149.168E-09
		Range	43.144E-09
Mean-3*StdDev	110.692E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.006, Test.Name=232 RX1 SKEW



Statistics: (S)

Min	119.621E-09	**StatLow**	N/A
Max	166.347E-09	**NWithinSpec**	N/A
Mean	141.115E-09	**NOutsideSpec**	N/A
StdDev	12.646E-09	**90%**	155.133E-09
25%	128.031E-09	**Range**	46.727E-09
Mean+3*StdDev	179.054E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	103.175E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0252		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

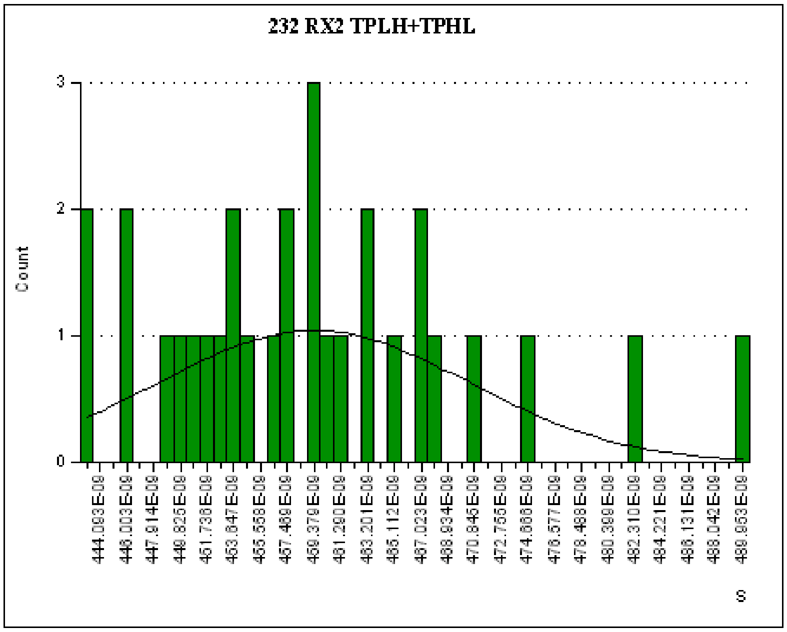
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.007, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

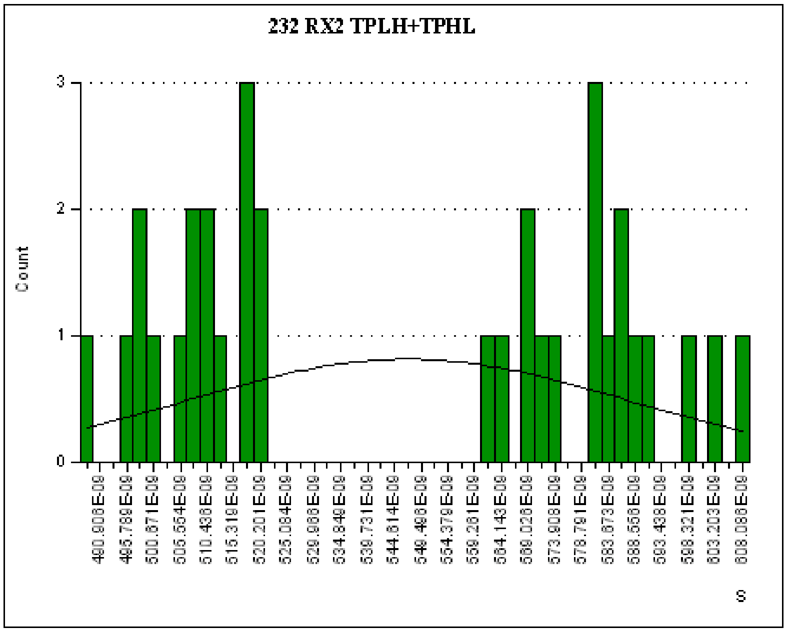
Min	443.137E-09	**Skew**	0.8869
Max	489.953E-09	**StatHigh**	N/A
Mean	459.202E-09	**StatLow**	N/A
StdDev	10.978E-09	**NWithinSpec**	N/A
25%	451.399E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	492.135E-09	**90%**	472.512E-09
		Range	46.816E-09
Mean-3*StdDev	426.268E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.007, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

Min	488.465E-09	**StatLow**	N/A
Max	608.086E-09	**NWithinSpec**	N/A
Mean	546.378E-09	**NOutsideSpec**	N/A
StdDev	39.355E-09	**90%**	590.330E-09
25%	509.959E-09	**Range**	119.621E-09
Mean+3*StdDev	664.443E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	428.313E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.0255		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

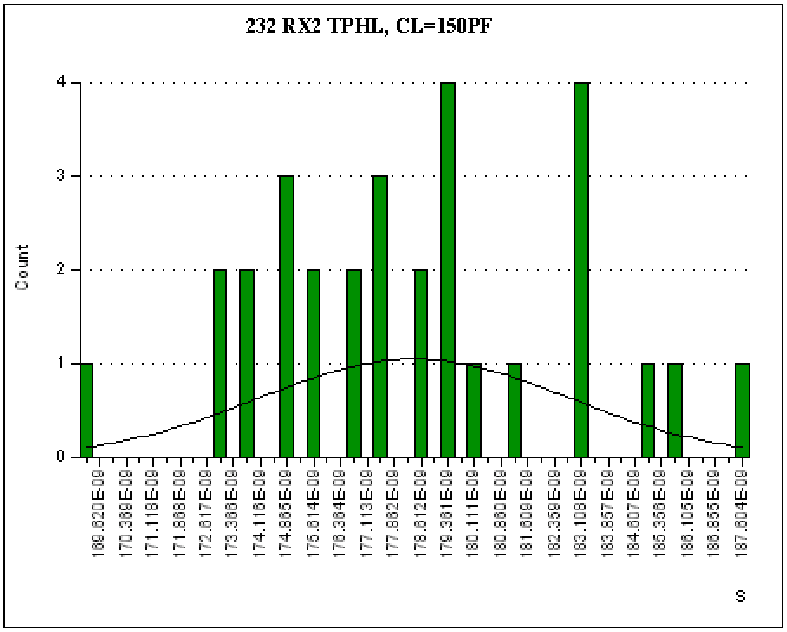
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.008, Test.Name=232 RX2 TPHL, CL=150PF



Statistics: (S)

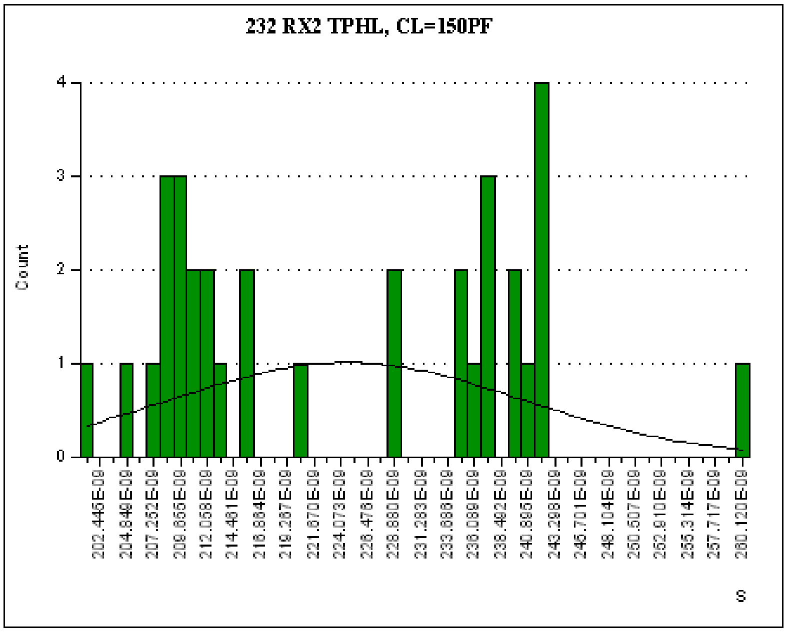
Min	169.245E-09	**Skew**	0.2327
Max	187.604E-09	**StatHigh**	N/A
Mean	178.333E-09	**StatLow**	N/A
StdDev	4.274E-09	**NWithinSpec**	N/A
25%	174.753E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	191.155E-09	**90%**	183.932E-09
		Range	18.359E-09
Mean-3*StdDev	165.510E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.008, Test.Name=232 RX2 TPHL, CL=150PF



Statistics: (S)

Min	201.244E-09	**StatLow**	N/A
Max	260.120E-09	**NWithinSpec**	N/A
Mean	224.352E-09	**NOutsideSpec**	N/A
StdDev	15.626E-09	**90%**	242.364E-09
25%	209.655E-09	**Range**	58.876E-09
Mean+3*StdDev	271.231E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	177.474E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2919		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

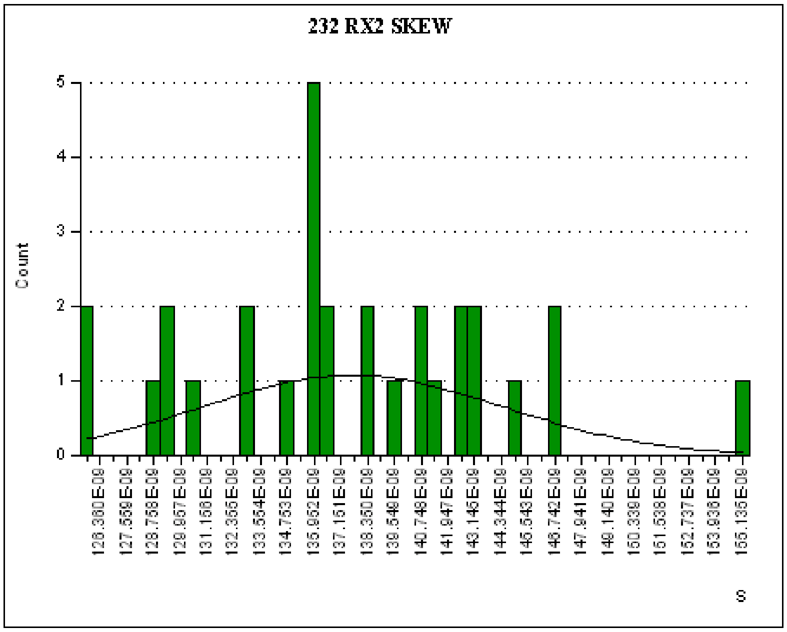
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.009, Test.Name=232 RX2 SKEW



Statistics: (S)

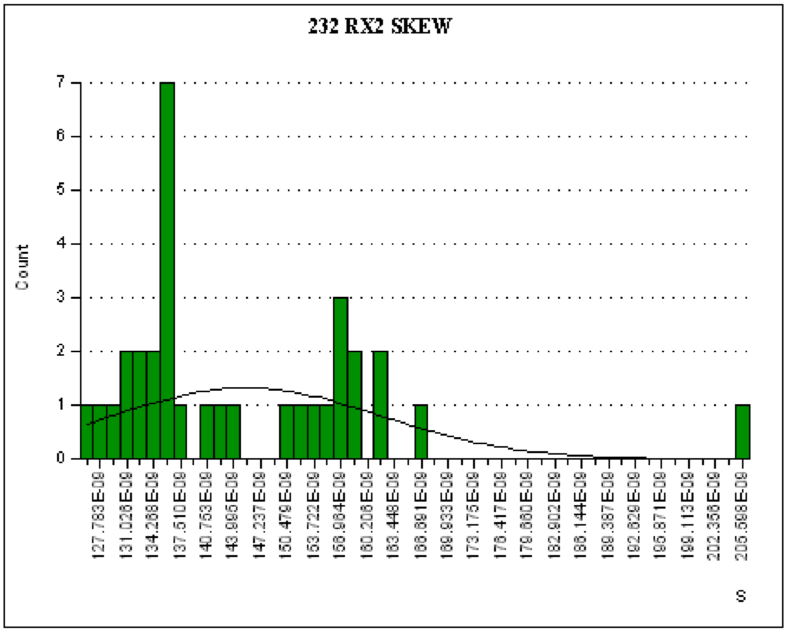
Min	125.760E-09	**Skew**	0.2995
Max	155.135E-09	**StatHigh**	N/A
Mean	137.572E-09	**StatLow**	N/A
StdDev	6.671E-09	**NWithinSpec**	N/A
25%	133.104E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	157.584E-09	**90%**	145.956E-09
		Range	29.375E-09
Mean-3*StdDev	117.559E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.009, Test.Name=232 RX2 SKEW



Statistics: (S)

Min	126.162E-09	**StatLow**	N/A
Max	205.598E-09	**NWithinSpec**	N/A
Mean	145.306E-09	**NOutsideSpec**	N/A
StdDev	16.096E-09	**90%**	162.609E-09
25%	134.573E-09	**Range**	79.436E-09
Mean+3*StdDev	193.593E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	97.020E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.7290		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

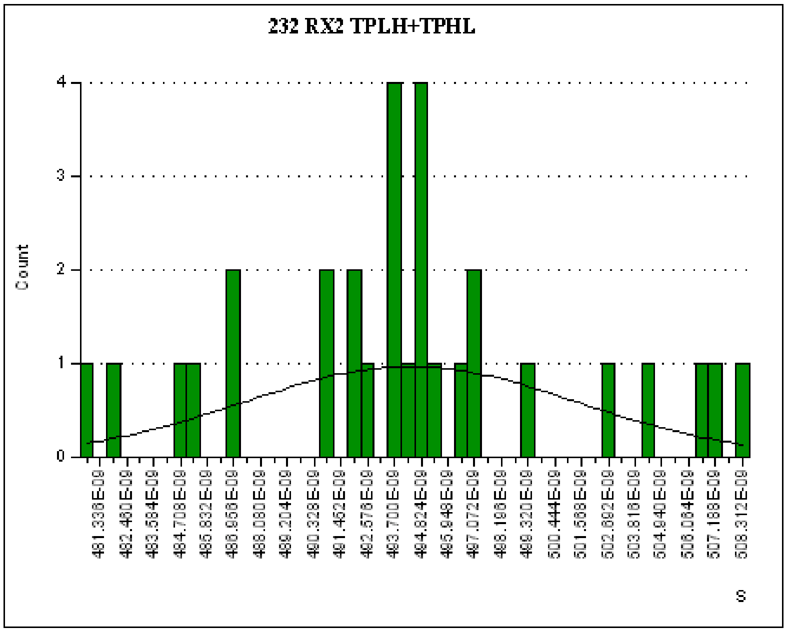
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.010, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

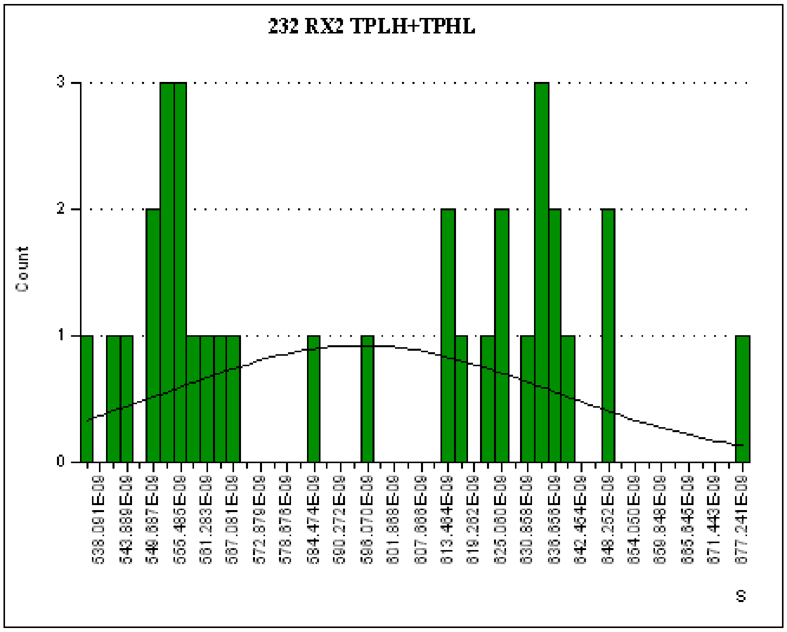
Min	480.774E-09	**Skew**	0.2176
Max	508.312E-09	**StatHigh**	N/A
Mean	494.237E-09	**StatLow**	N/A
StdDev	6.955E-09	**NWithinSpec**	N/A
25%	490.871E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	515.102E-09	**90%**	505.558E-09
		Range	27.539E-09
Mean-3*StdDev	473.372E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.010, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

Min	535.192E-09	**StatLow**	N/A
Max	677.241E-09	**NWithinSpec**	N/A
Mean	594.011E-09	**NOutsideSpec**	N/A
StdDev	41.335E-09	**90%**	639.860E-09
25%	554.817E-09	**Range**	142.049E-09
Mean+3*StdDev	718.017E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	470.005E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.1388		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

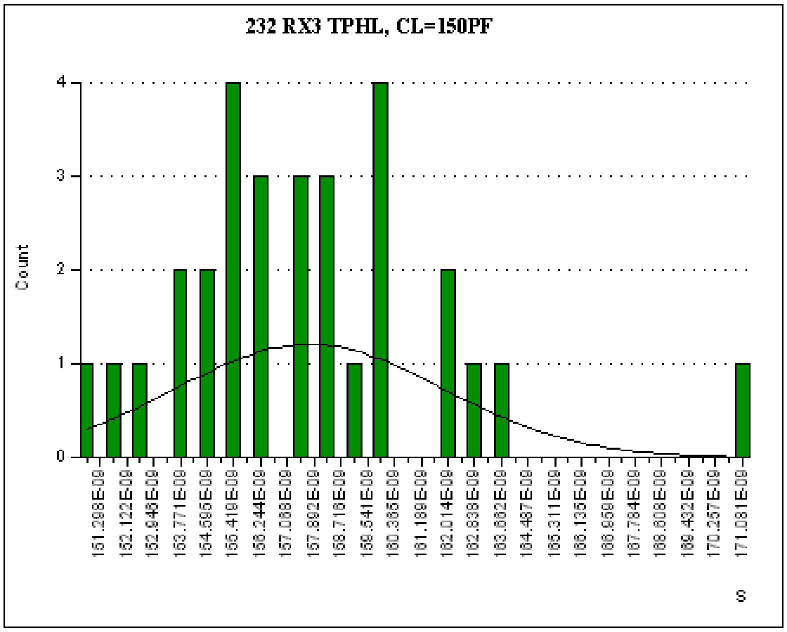
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.011, Test.Name=232 RX3 TPHL, CL=150PF



Statistics: (S)

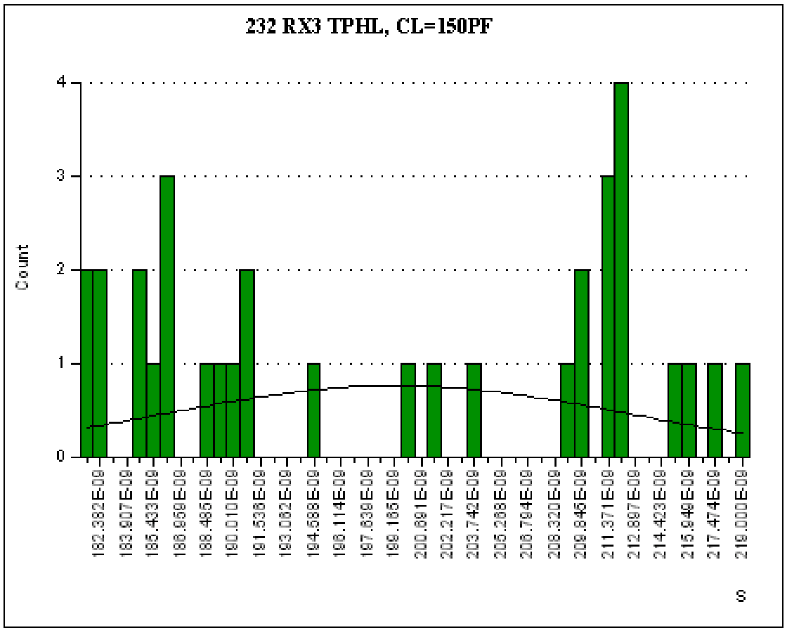
Min	150.886E-09	**Skew**	1.1265
Max	171.081E-09	**StatHigh**	N/A
Mean	157.679E-09	**StatLow**	N/A
StdDev	4.095E-09	**NWithinSpec**	N/A
25%	155.476E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	169.965E-09	**90%**	162.360E-09
		Range	20.195E-09
Mean-3*StdDev	145.393E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.011, Test.Name=232 RX3 TPHL, CL=150PF



Statistics: (S)

Min	181.619E-09	**StatLow**	N/A
Max	219.000E-09	**NWithinSpec**	N/A
Mean	199.120E-09	**NOutsideSpec**	N/A
StdDev	13.136E-09	**90%**	215.262E-09
25%	186.291E-09	**Range**	37.381E-09
Mean+3*StdDev	238.528E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	159.712E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0309		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

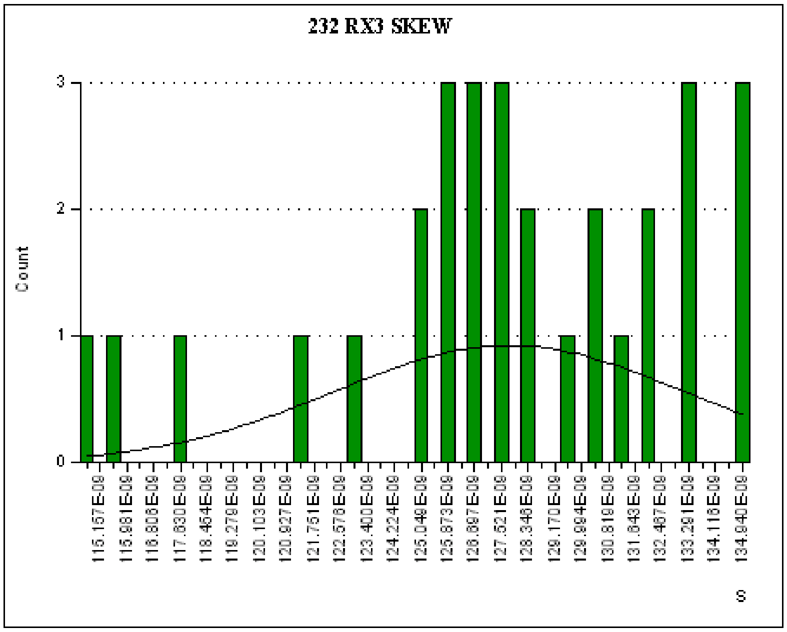
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.012, Test.Name=232 RX3 SKEW



Statistics: (S)

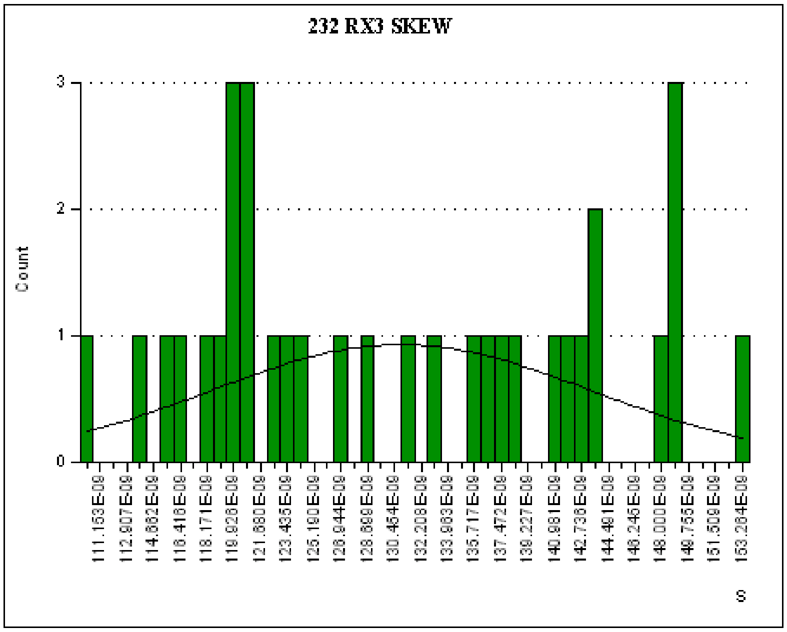
Min	114.745E-09	**Skew**	-0.8158
Max	134.940E-09	**StatHigh**	N/A
Mean	127.627E-09	**StatLow**	N/A
StdDev	5.344E-09	**NWithinSpec**	N/A
25%	125.760E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	143.660E-09	**90%**	134.022E-09
		Range	20.195E-09
Mean-3*StdDev	111.594E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.012, Test.Name=232 RX3 SKEW



Statistics: (S)

Min	110.275E-09	**StatLow**	N/A
Max	153.264E-09	**NWithinSpec**	N/A
Mean	130.693E-09	**NOutsideSpec**	N/A
StdDev	12.418E-09	**90%**	148.591E-09
25%	119.621E-09	**Range**	42.989E-09
Mean+3*StdDev	167.948E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	93.439E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2130		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

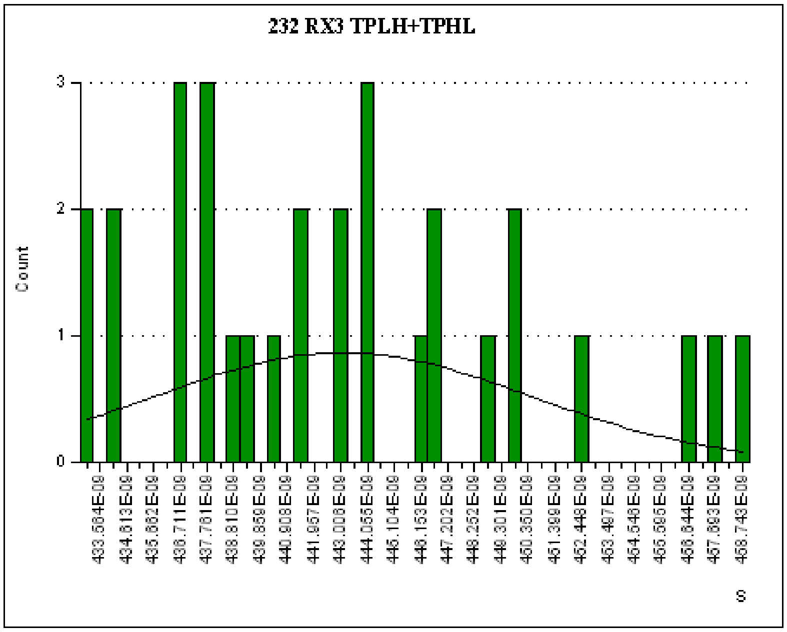
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.013, Test.Name=232 RX3 TPLH+TPHL



Statistics: (S)

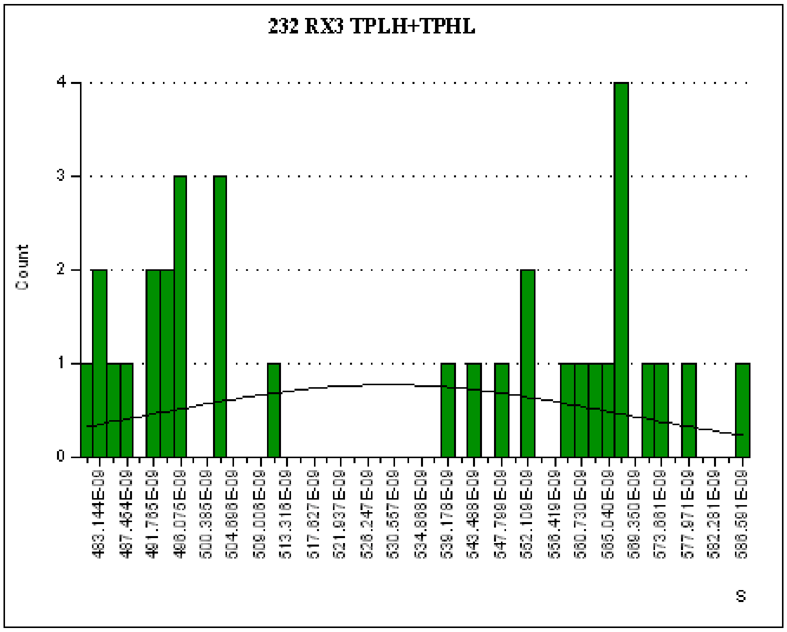
Min	433.040E-09	**Skew**	0.6617
Max	458.743E-09	**StatHigh**	N/A
Mean	442.984E-09	**StatLow**	N/A
StdDev	7.236E-09	**NWithinSpec**	N/A
25%	437.629E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	464.693E-09	**90%**	454.612E-09
		Range	25.703E-09
Mean-3*StdDev	421.275E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.013, Test.Name=232 RX3 TPLH+TPHL



Statistics: (S)

Min	480.989E-09	**StatLow**	N/A
Max	586.591E-09	**NWithinSpec**	N/A
Mean	528.933E-09	**NOutsideSpec**	N/A
StdDev	36.638E-09	**90%**	572.573E-09
25%	493.138E-09	**Range**	105.603E-09
Mean+3*StdDev	638.847E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	419.020E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0390		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

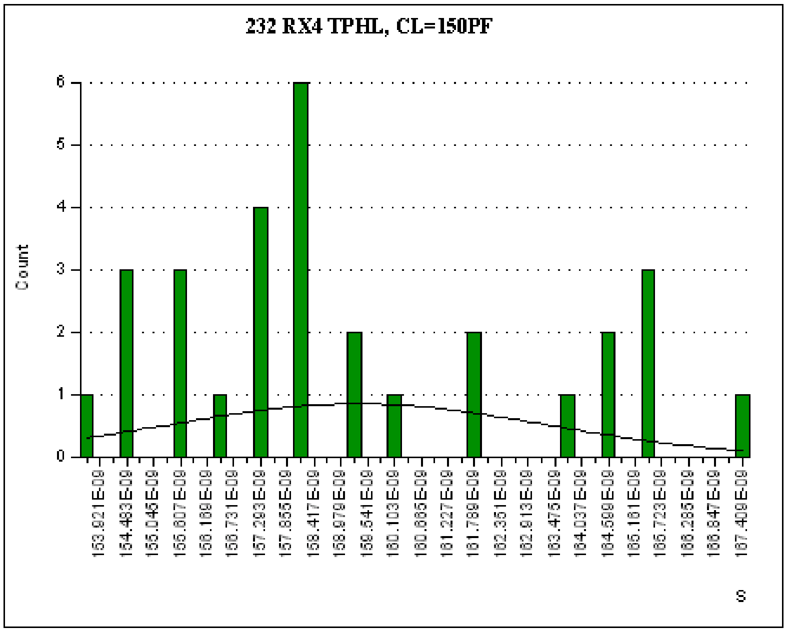
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.014, Test.Name=232 RX4 TPHL, CL=150PF



Statistics: (S)

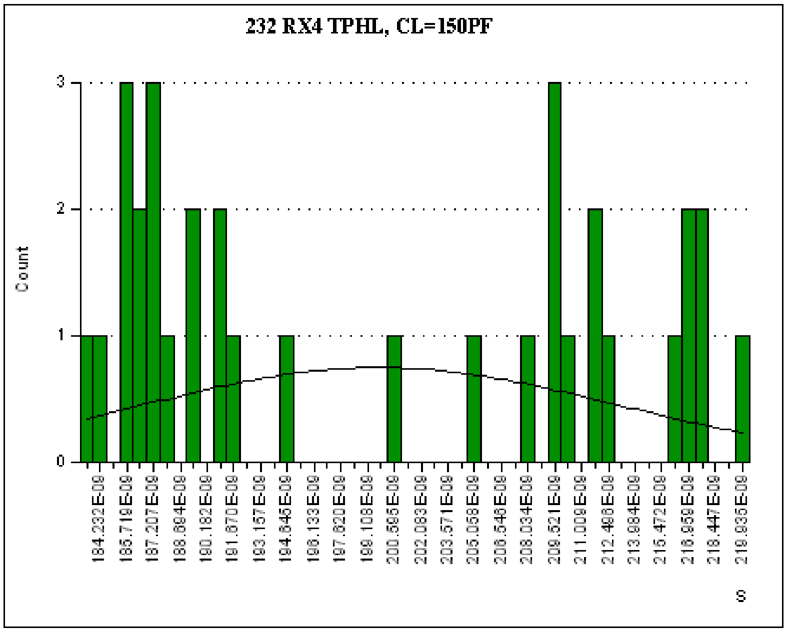
Min	153.640E-09	**Skew**	0.6128
Max	167.409E-09	**StatHigh**	N/A
Mean	159.270E-09	**StatLow**	N/A
StdDev	3.937E-09	**NWithinSpec**	N/A
25%	156.393E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	171.081E-09	**90%**	165.573E-09
		Range	13.769E-09
Mean-3*StdDev	147.458E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.014, Test.Name=232 RX4 TPHL, CL=150PF



Statistics: (S)

Min	183.488E-09	**StatLow**	N/A
Max	219.935E-09	**NWithinSpec**	N/A
Mean	199.630E-09	**NOutsideSpec**	N/A
StdDev	13.053E-09	**90%**	217.131E-09
25%	187.226E-09	**Range**	36.447E-09
Mean+3*StdDev	238.788E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	160.472E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2100		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

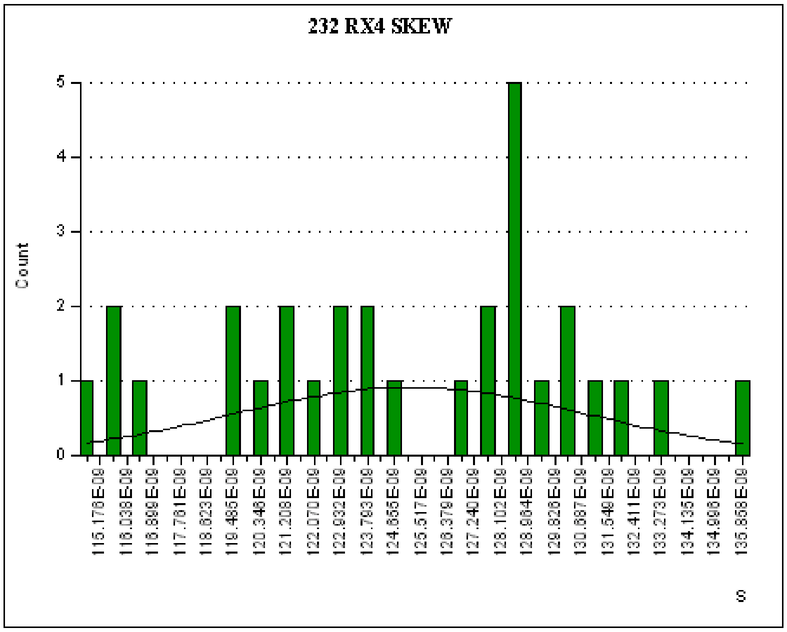
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.015, Test.Name=232 RX4 SKEW



Statistics: (S)

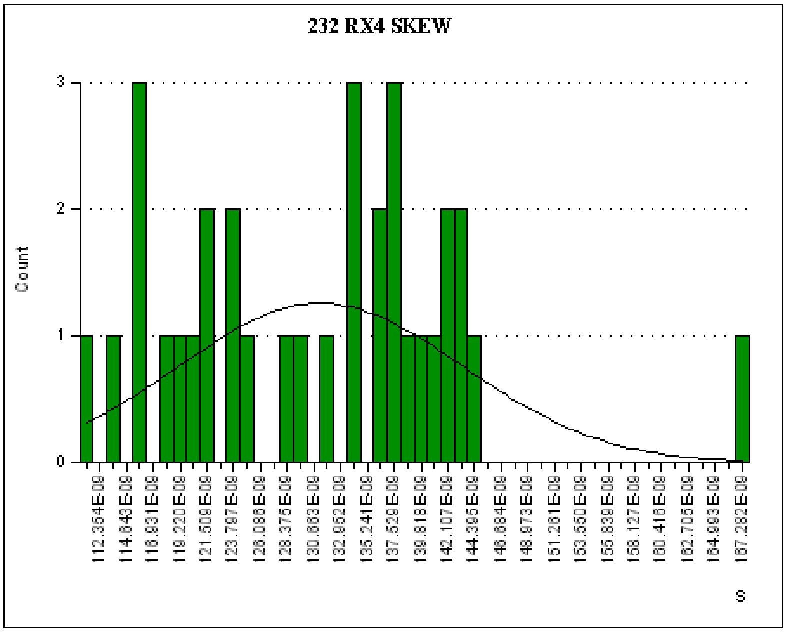
Min	114.745E-09	**Skew**	-0.2096
Max	135.858E-09	**StatHigh**	N/A
Mean	125.057E-09	**StatLow**	N/A
StdDev	5.616E-09	**NWithinSpec**	N/A
25%	121.171E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	141.904E-09	**90%**	131.727E-09
		Range	21.113E-09
Mean-3*StdDev	108.209E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.015, Test.Name=232 RX4 SKEW



Statistics: (S)

Min	111.210E-09	**StatLow**	N/A
Max	167.282E-09	**NWithinSpec**	N/A
Mean	131.033E-09	**NOutsideSpec**	N/A
StdDev	11.976E-09	**90%**	142.984E-09
25%	121.490E-09	**Range**	56.072E-09
Mean+3*StdDev	166.963E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	95.104E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.5350		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

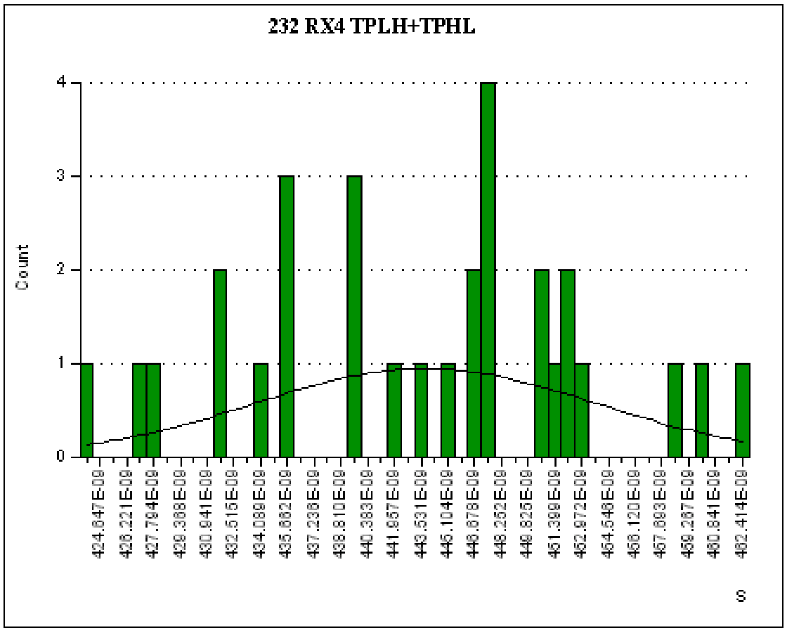
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.016, Test.Name=232 RX4 TPLH+TPHL



Statistics: (S)

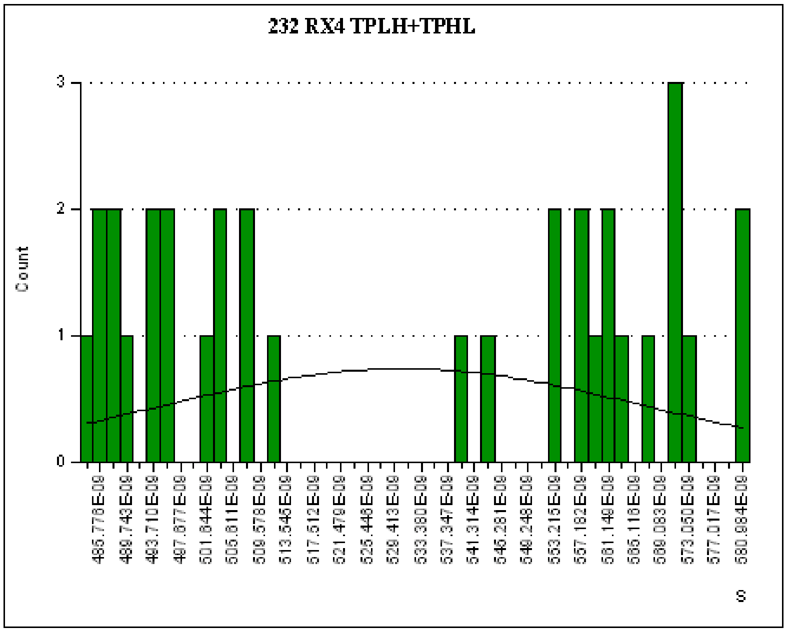
Min	423.860E-09	**Skew**	-0.1622
Max	462.414E-09	**StatHigh**	N/A
Mean	443.596E-09	**StatLow**	N/A
StdDev	9.933E-09	**NWithinSpec**	N/A
25%	435.794E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	473.395E-09	**90%**	455.989E-09
		Range	38.554E-09
Mean-3*StdDev	413.797E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.016, Test.Name=232 RX4 TPLH+TPHL



Statistics: (S)

Min	483.793E-09	**StatLow**	N/A
Max	580.984E-09	**NWithinSpec**	N/A
Mean	530.293E-09	**NOutsideSpec**	N/A
StdDev	35.190E-09	**90%**	571.639E-09
25%	495.007E-09	**Range**	97.192E-09
Mean+3*StdDev	635.864E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	424.721E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0116		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

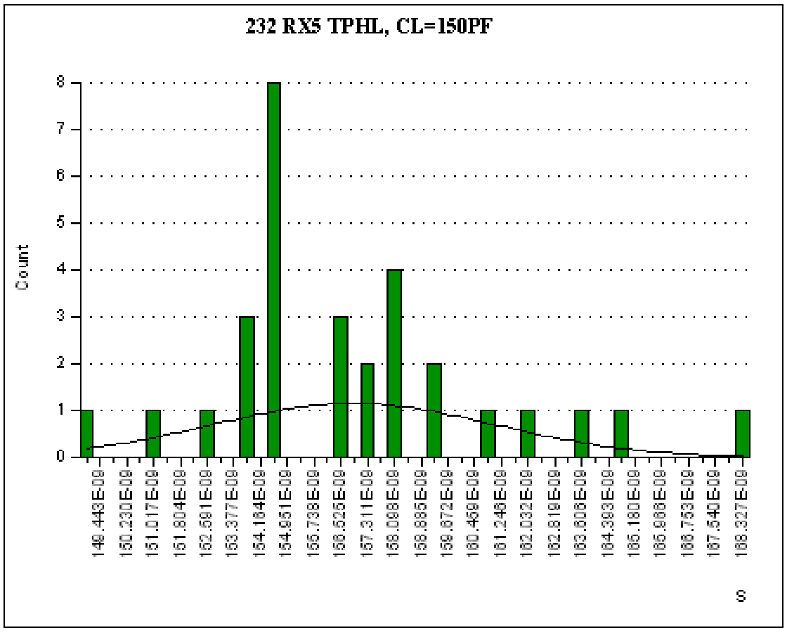
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.017, Test.Name=232 RX5 TPHL, CL=150PF



Statistics: (S)

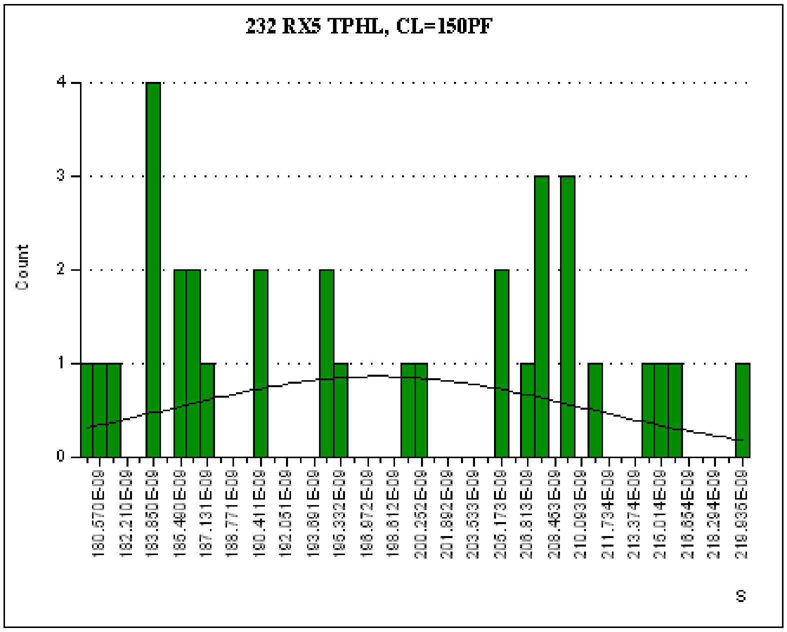
Min	149.050E-09	**Skew**	0.8751
Max	168.327E-09	**StatHigh**	N/A
Mean	156.822E-09	**StatLow**	N/A
StdDev	4.103E-09	**NWithinSpec**	N/A
25%	154.558E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	169.132E-09	**90%**	162.819E-09
		Range	19.277E-09
Mean-3*StdDev	144.512E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.017, Test.Name=232 RX5 TPHL, CL=150PF



Statistics: (S)

Min	179.750E-09	**StatLow**	N/A
Max	219.935E-09	**NWithinSpec**	N/A
Mean	197.477E-09	**NOutsideSpec**	N/A
StdDev	12.515E-09	**90%**	214.327E-09
25%	185.357E-09	**Range**	40.185E-09
Mean+3*StdDev	235.023E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	159.932E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.1254		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

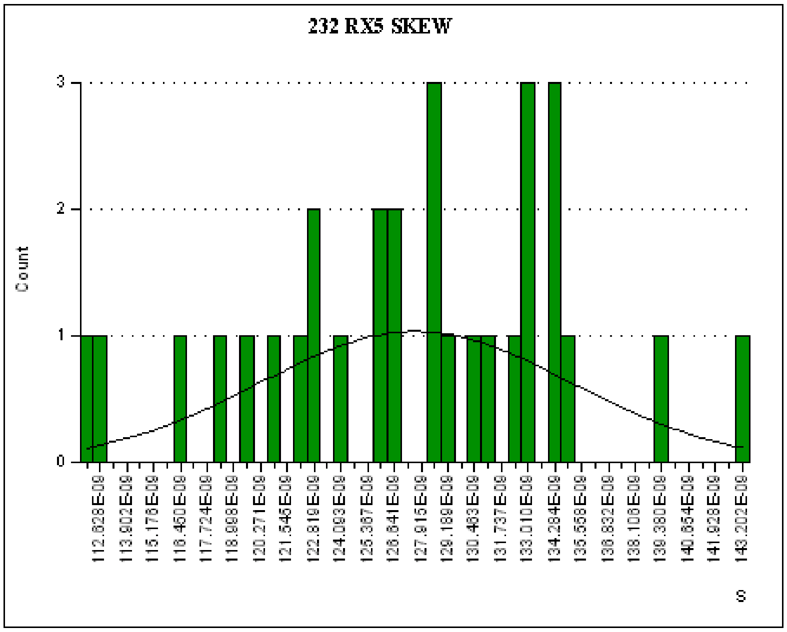
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.018, Test.Name=232 RX5 SKEW



Statistics: (S)

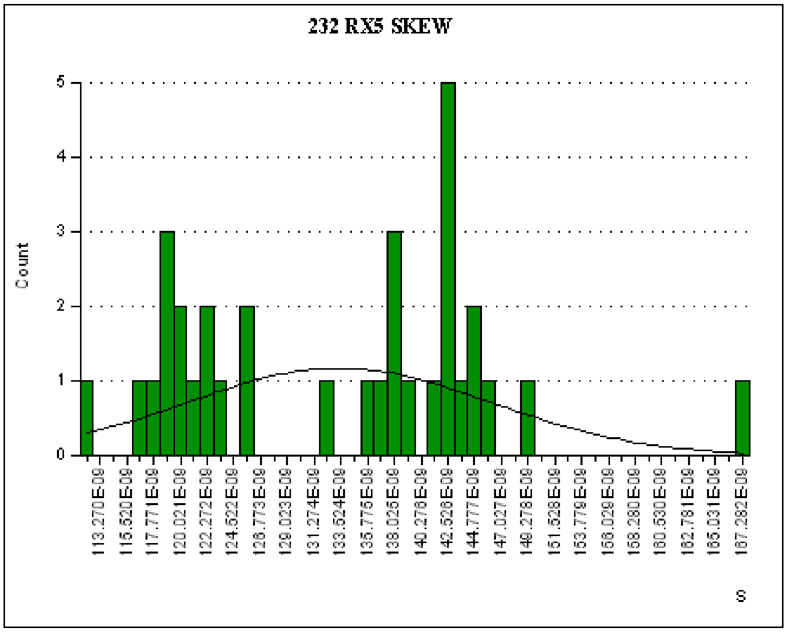
Min	111.991E-09	**Skew**	-0.2344
Max	143.202E-09	**StatHigh**	N/A
Mean	127.505E-09	**StatLow**	N/A
StdDev	7.361E-09	**NWithinSpec**	N/A
25%	123.007E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	149.587E-09	**90%**	134.481E-09
		Range	31.211E-09
Mean-3*StdDev	105.422E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.018, Test.Name=232 RX5 SKEW



Statistics: (S)

Min	112.144E-09	**StatLow**	N/A
Max	167.282E-09	**NWithinSpec**	N/A
Mean	133.185E-09	**NOutsideSpec**	N/A
StdDev	12.636E-09	**90%**	144.853E-09
25%	121.490E-09	**Range**	55.138E-09
Mean+3*StdDev	171.093E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	95.278E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3145		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

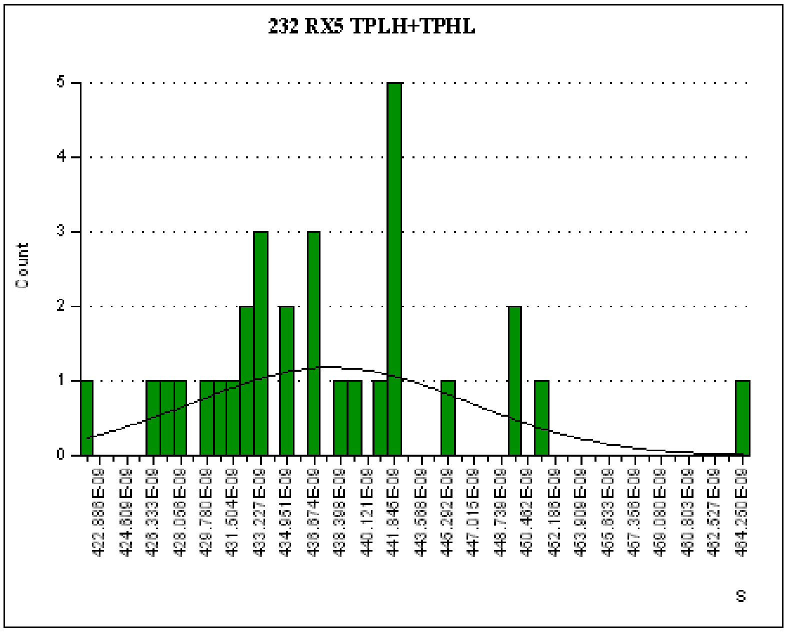
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=16.019, Test.Name=232 RX5 TPLH+TPHL



Statistics: (S)

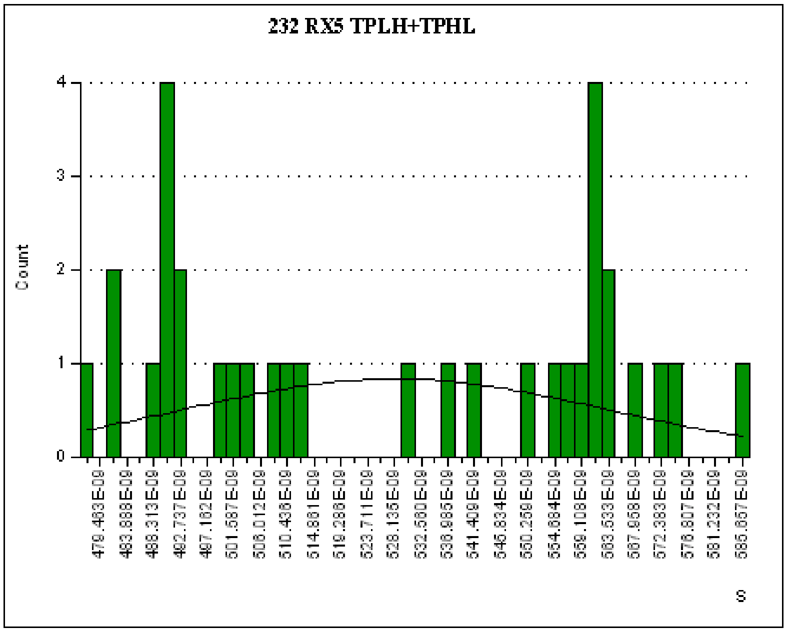
Min	422.024E-09	**Skew**	0.9389
Max	464.250E-09	**StatHigh**	N/A
Mean	437.629E-09	**StatLow**	N/A
StdDev	8.742E-09	**NWithinSpec**	N/A
25%	432.122E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	463.855E-09	**90%**	449.563E-09
		Range	42.226E-09
Mean-3*StdDev	411.404E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.019, Test.Name=232 RX5 TPLH+TPHL



Statistics: (S)

Min	477.251E-09	**StatLow**	N/A
Max	585.657E-09	**NWithinSpec**	N/A
Mean	527.801E-09	**NOutsideSpec**	N/A
StdDev	34.844E-09	**90%**	568.835E-09
25%	492.203E-09	**Range**	108.406E-09
Mean+3*StdDev	632.332E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	423.269E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0260		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

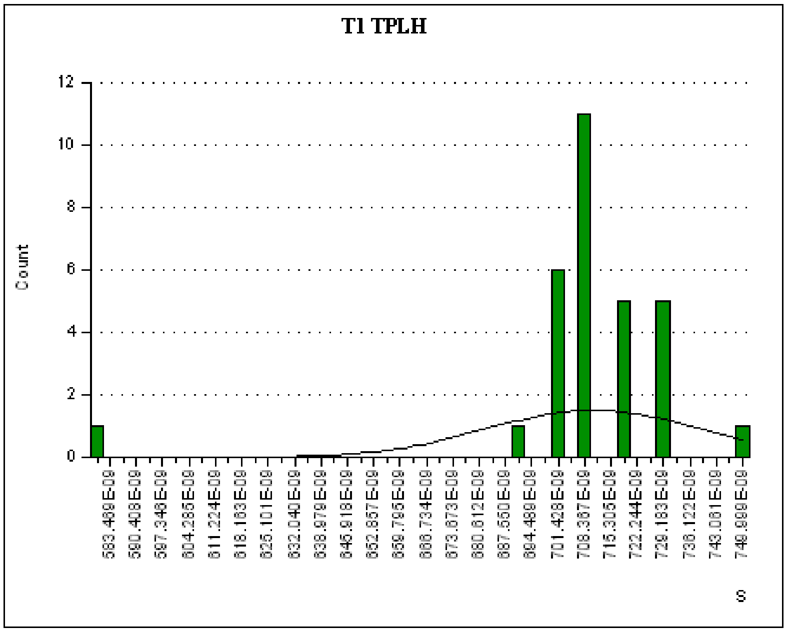
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=17.000, Test.Name=T1 TPLH



Statistics: (S)

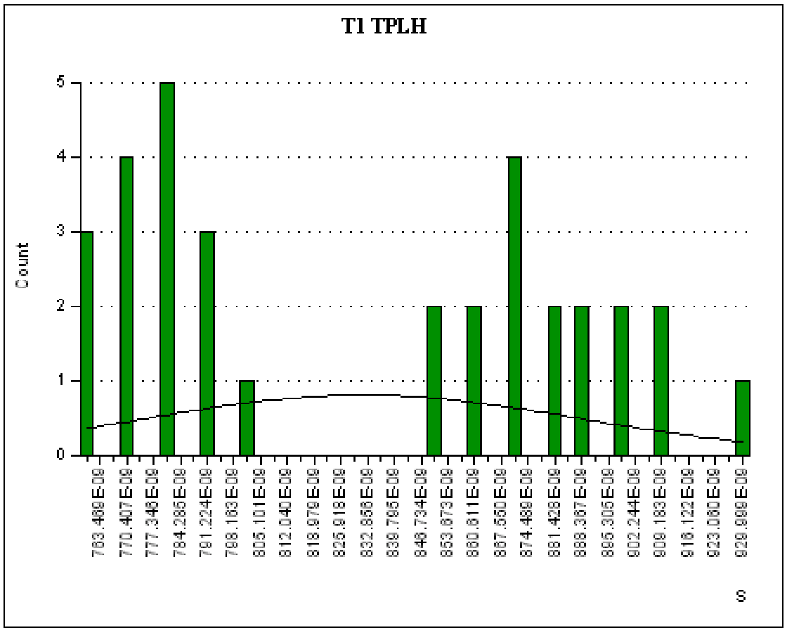
Min	579.999E-09	**Skew**	-3.6423
Max	749.999E-09	**StatHigh**	N/A
Mean	709.333E-09	**StatLow**	N/A
StdDev	27.535E-09	**NWithinSpec**	N/A
25%	699.999E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	791.937E-09	**90%**	729.999E-09
		Range	170.000E-09
Mean-3*StdDev	626.729E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.000, Test.Name=T1 TPLH



Statistics: (S)

Min	759.999E-09	**StatLow**	N/A
Max	929.999E-09	**NWithinSpec**	N/A
Mean	830.908E-09	**NOutsideSpec**	N/A
StdDev	56.201E-09	**90%**	899.999E-09
25%	779.999E-09	**Range**	170.000E-09
Mean+3*StdDev	999.510E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	662.306E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.1322		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

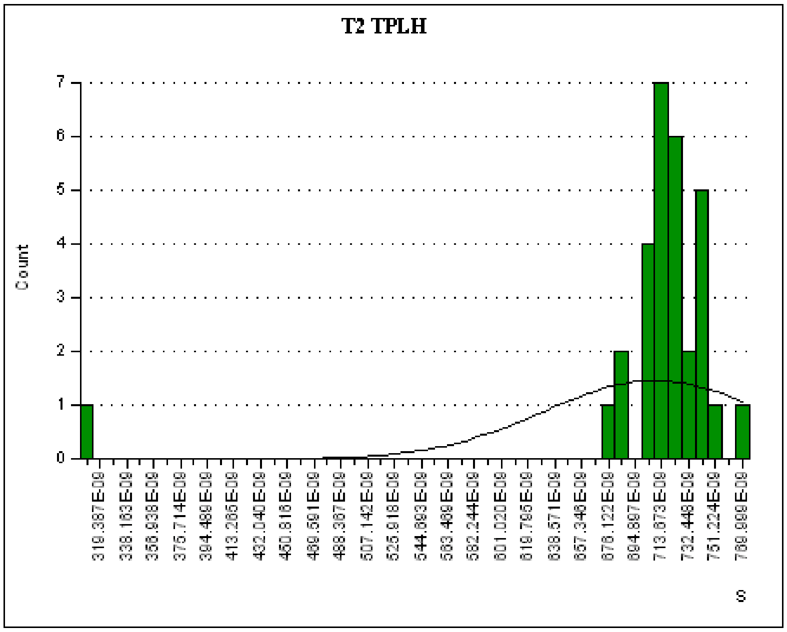
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=17.001, Test.Name=T2 TPLH



Statistics: (S)

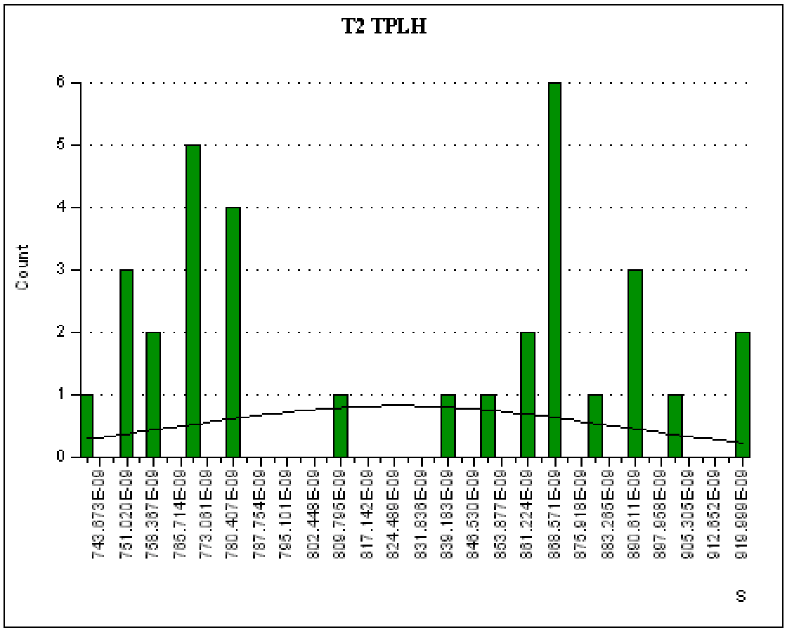
Min	310.000E-09	**Skew**	-4.9069
Max	769.999E-09	**StatHigh**	N/A
Mean	704.666E-09	**StatLow**	N/A
StdDev	77.091E-09	**NWithinSpec**	N/A
25%	699.999E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	935.938E-09	**90%**	739.999E-09
		Range	460.000E-09
Mean-3*StdDev	473.394E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.001, Test.Name=T2 TPLH



Statistics: (S)

Min	739.999E-09	**StatLow**	N/A
Max	919.999E-09	**NWithinSpec**	N/A
Mean	824.545E-09	**NOutsideSpec**	N/A
StdDev	58.848E-09	**90%**	889.999E-09
25%	769.999E-09	**Range**	180.000E-09
Mean+3*StdDev	1.001E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	648.001E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0491		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

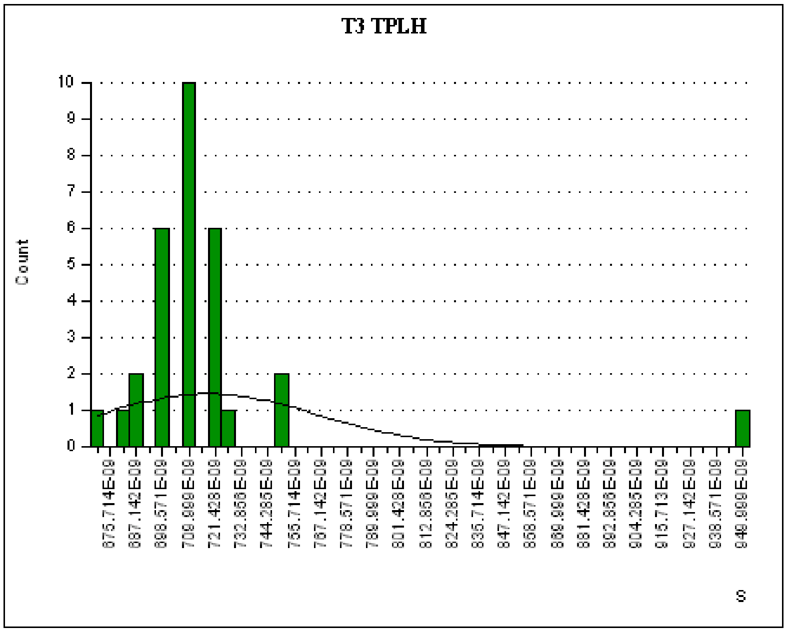
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=17.002, Test.Name=T3 TPLH



Statistics: (S)

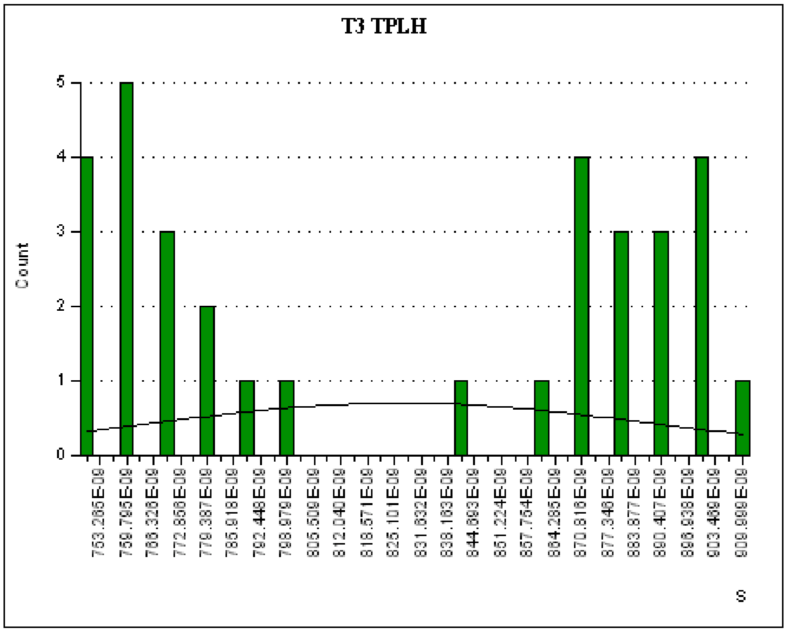
Min	669.999E-09	**Skew**	4.4144
Max	949.999E-09	**StatHigh**	N/A
Mean	717.666E-09	**StatLow**	N/A
StdDev	46.954E-09	**NWithinSpec**	N/A
25%	699.999E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	858.529E-09	**90%**	739.999E-09
		Range	280.000E-09
Mean-3*StdDev	576.803E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.002, Test.Name=T3 TPLH



Statistics: (S)

Min	749.999E-09	**StatLow**	N/A
Max	909.999E-09	**NWithinSpec**	N/A
Mean	826.060E-09	**NOutsideSpec**	N/A
StdDev	61.132E-09	**90%**	899.999E-09
25%	759.999E-09	**Range**	160.000E-09
Mean+3*StdDev	1.009E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	642.664E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0212		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

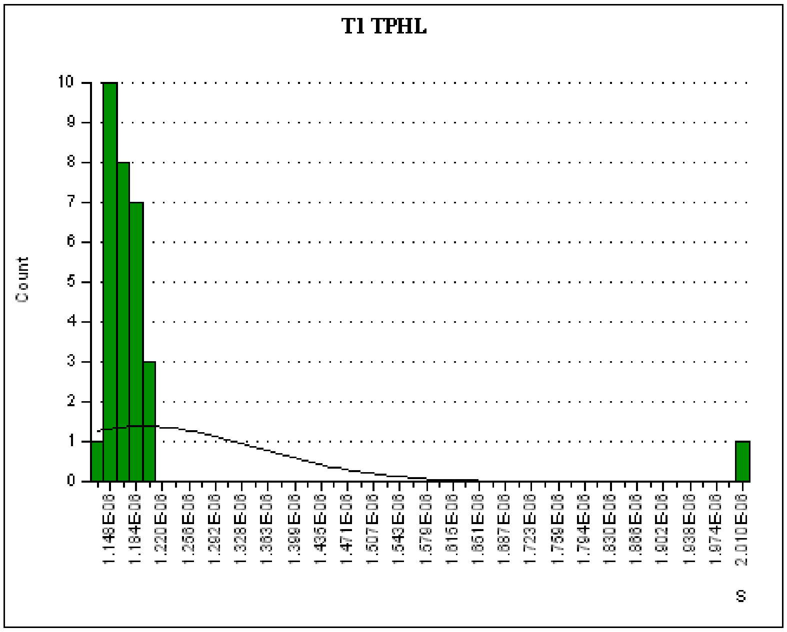
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=17.003, Test.Name=T1 TPHL



Statistics: (S)

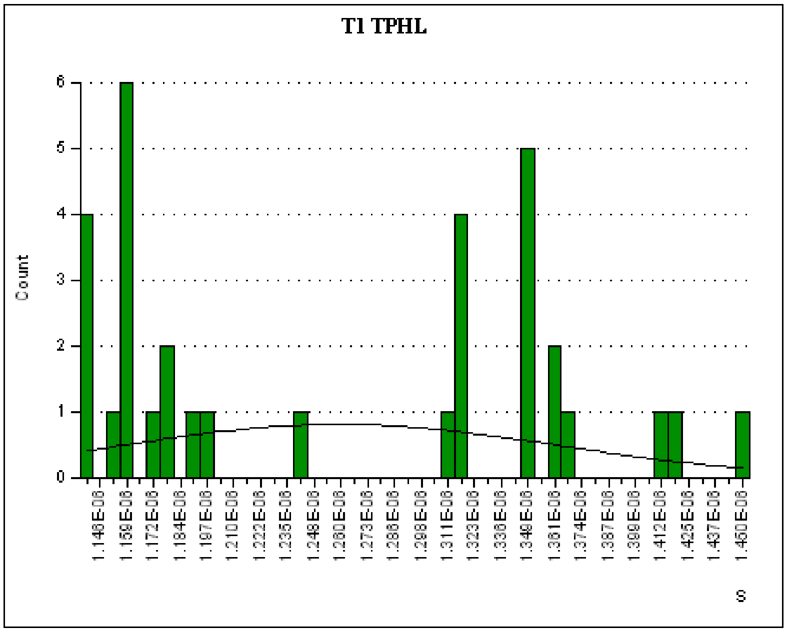
Min	1.130E-06	**Skew**	5.3266
Max	2.010E-06	**StatHigh**	N/A
Mean	1.193E-06	**StatLow**	N/A
StdDev	155.655E-09	**NWithinSpec**	N/A
25%	1.150E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.660E-06	**90%**	1.200E-06
		Range	879.999E-09
Mean-3*StdDev	726.033E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.003, Test.Name=T1 TPHL



Statistics: (S)

Min	1.140E-06	**StatLow**	N/A
Max	1.450E-06	**NWithinSpec**	N/A
Mean	1.259E-06	**NOutsideSpec**	N/A
StdDev	102.034E-09	**90%**	1.370E-06
25%	1.160E-06	**Range**	309.999E-09
Mean+3*StdDev	1.565E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	952.684E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.2174		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

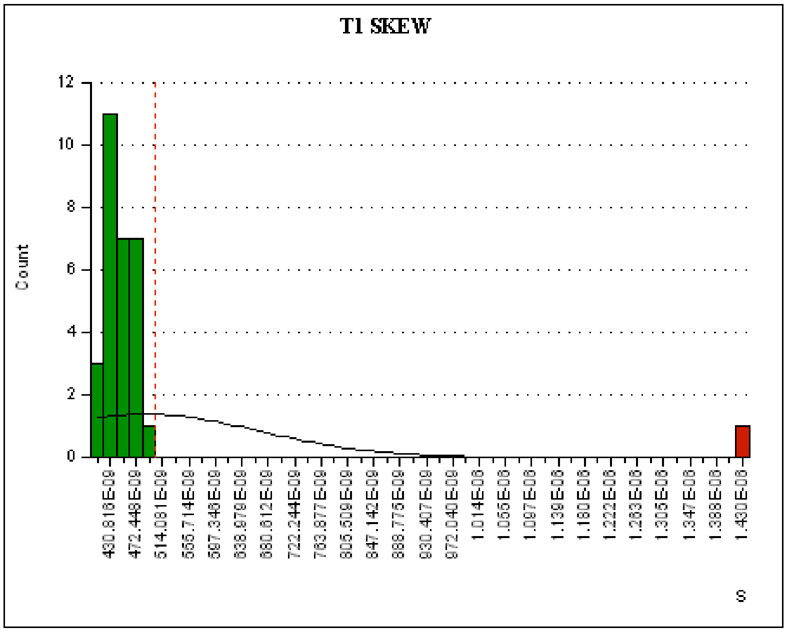
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 01:29 PM

Test.Number=17.004, Test.Name=T1 SKEW



Statistics: (S)

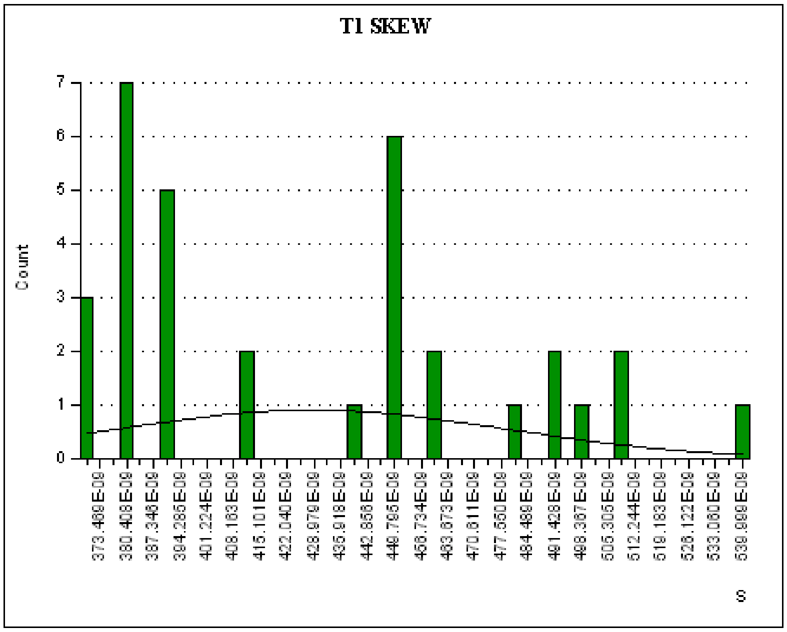
Min	410.000E-09	**Skew**	5.3484
Max	1.430E-06	**StatHigh**	N/A
Mean	483.666E-09	**StatLow**	N/A
StdDev	180.067E-09	**NWithinSpec**	29
25%	439.999E-09	**NOutsideSpec**	1
Mean+3*StdDev	1.024E-06	**90%**	479.999E-09
		Range	1.020E-06
Mean-3*StdDev	-56.534E-09	**NOutsideSpec**	1
Cpk	0.0302		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.004, Test.Name=T1 SKEW



Statistics: (S)

Min	369.999E-09	**StatLow**	N/A
Max	539.999E-09	**NWithinSpec**	N/A
Mean	427.878E-09	**NOutsideSpec**	N/A
StdDev	50.234E-09	**90%**	499.999E-09
25%	380.000E-09	**Range**	170.000E-09
Mean+3*StdDev	578.581E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	277.175E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.5283		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

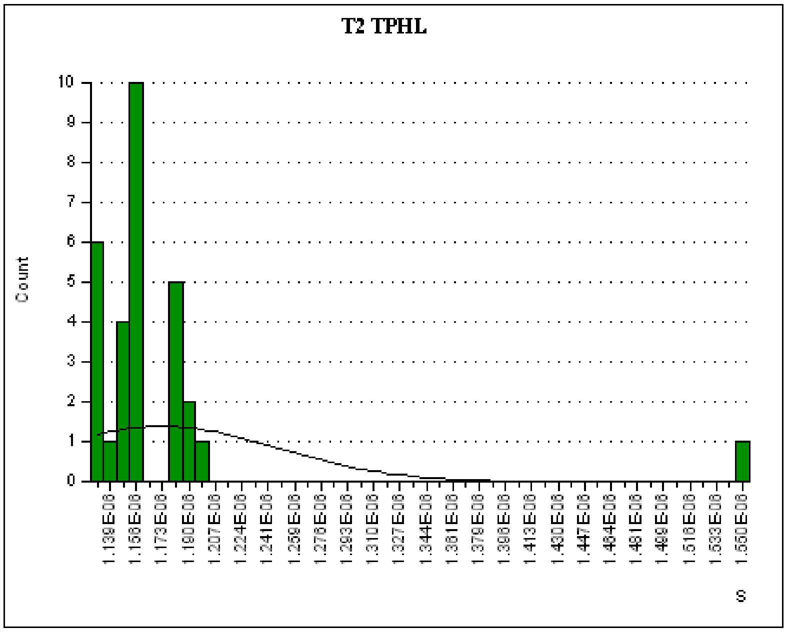
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=17.005, Test.Name=T2 TPHL



Statistics: (S)

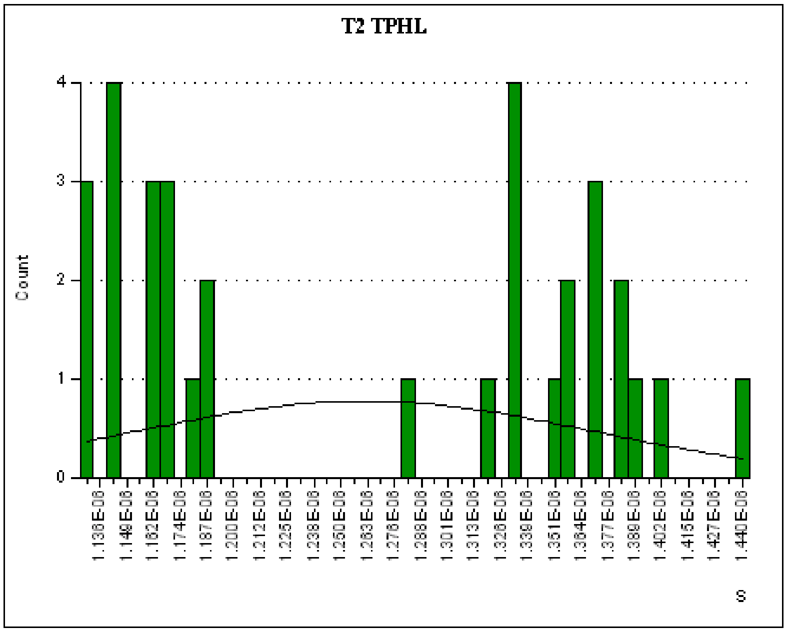
Min	1.130E-06	**Skew**	4.8559
Max	1.550E-06	**StatHigh**	N/A
Mean	1.172E-06	**StatLow**	N/A
StdDev	74.189E-09	**NWithinSpec**	N/A
25%	1.150E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.394E-06	**90%**	1.190E-06
		Range	419.999E-09
Mean-3*StdDev	949.098E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.005, Test.Name=T2 TPHL



Statistics: (S)

Min	1.130E-06	**StatLow**	N/A
Max	1.440E-06	**NWithinSpec**	N/A
Mean	1.260E-06	**NOutsideSpec**	N/A
StdDev	106.726E-09	**90%**	1.380E-06
25%	1.160E-06	**Range**	309.999E-09
Mean+3*StdDev	1.580E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	940.123E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.0637		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

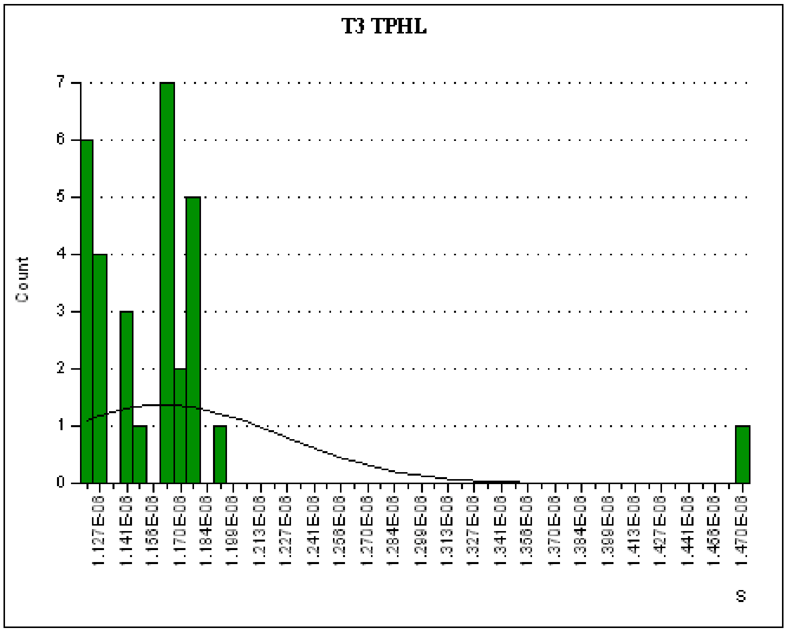
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=17.007, Test.Name=T3 TPHL



Statistics: (S)

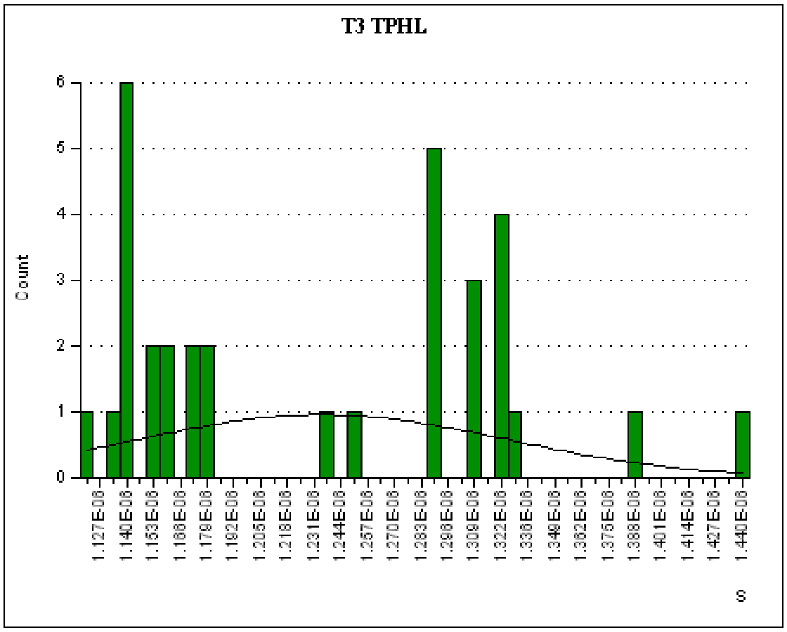
Min	1.120E-06	**Skew**	4.3664
Max	1.470E-06	**StatHigh**	N/A
Mean	1.161E-06	**StatLow**	N/A
StdDev	62.607E-09	**NWithinSpec**	N/A
25%	1.130E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.349E-06	**90%**	1.180E-06
		Range	350.000E-09
Mean-3*StdDev	973.177E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.007, Test.Name=T3 TPHL



Statistics: (S)

Min	1.120E-06	**StatLow**	N/A
Max	1.440E-06	**NWithinSpec**	N/A
Mean	1.234E-06	**NOutsideSpec**	N/A
StdDev	89.231E-09	**90%**	1.320E-06
25%	1.150E-06	**Range**	320.000E-09
Mean+3*StdDev	1.502E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	966.246E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3647		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

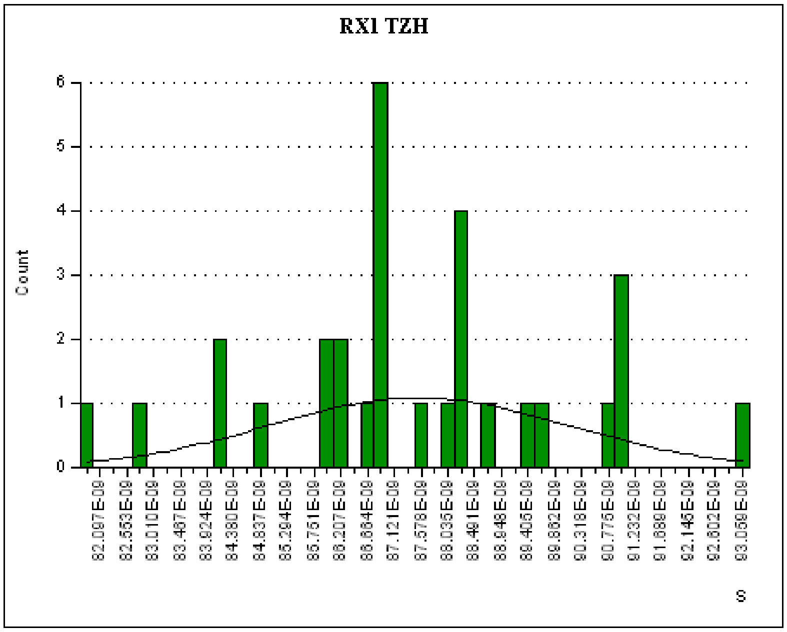
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.000, Test.Name=RX1 TZH



Statistics: (S)

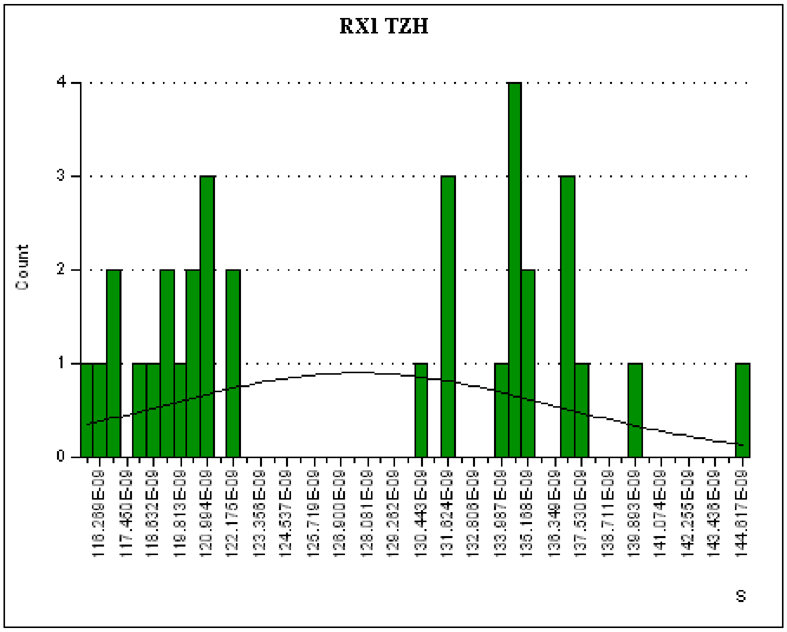
Min	81.868E-09	**Skew**	-0.0164
Max	93.059E-09	**StatHigh**	N/A
Mean	87.475E-09	**StatLow**	N/A
StdDev	2.504E-09	**NWithinSpec**	N/A
25%	86.277E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	94.988E-09	**90%**	91.024E-09
		Range	11.191E-09
Mean-3*StdDev	79.962E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.000, Test.Name=RX1 TZH



Statistics: (S)

Min	115.679E-09	**StatLow**	N/A
Max	144.617E-09	**NWithinSpec**	N/A
Mean	127.538E-09	**NOutsideSpec**	N/A
StdDev	8.631E-09	**90%**	137.038E-09
25%	119.813E-09	**Range**	28.939E-09
Mean+3*StdDev	153.432E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	101.644E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.1320		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

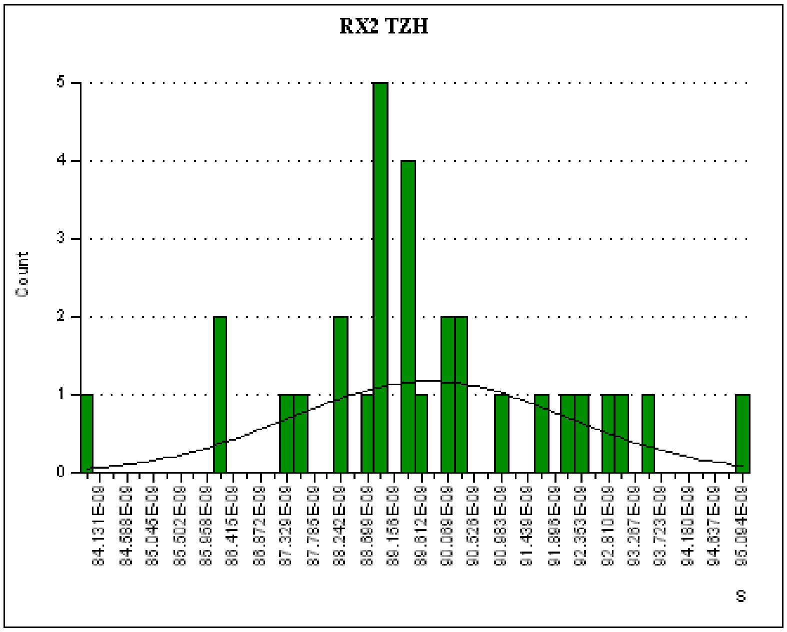
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.001, Test.Name=RX2 TZH



Statistics: (S)

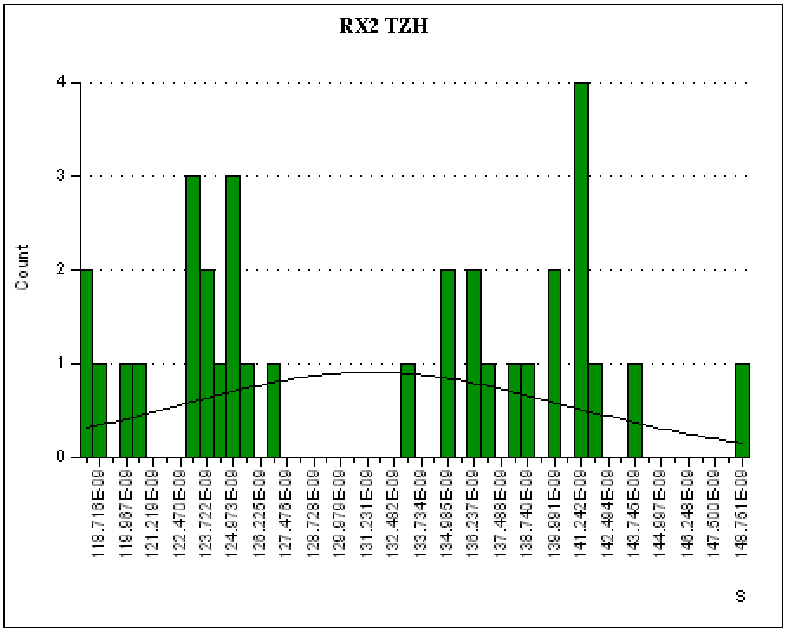
Min	83.903E-09	**Skew**	0.0413
Max	95.094E-09	**StatHigh**	N/A
Mean	89.690E-09	**StatLow**	N/A
StdDev	2.332E-09	**NWithinSpec**	N/A
25%	88.650E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	96.688E-09	**90%**	92.889E-09
		Range	11.191E-09
Mean-3*StdDev	82.693E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.001, Test.Name=RX2 TZH



Statistics: (S)

Min	118.090E-09	**StatLow**	N/A
Max	148.751E-09	**NWithinSpec**	N/A
Mean	131.317E-09	**NOutsideSpec**	N/A
StdDev	9.077E-09	**90%**	141.517E-09
25%	123.602E-09	**Range**	30.661E-09
Mean+3*StdDev	158.548E-09	**NOutsideSpec**	N/A
Mean-3*StdDev	104.087E-09	**Cp**	N/A
Cpk	N/A	**Cpl**	N/A
Skew	0.0855	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

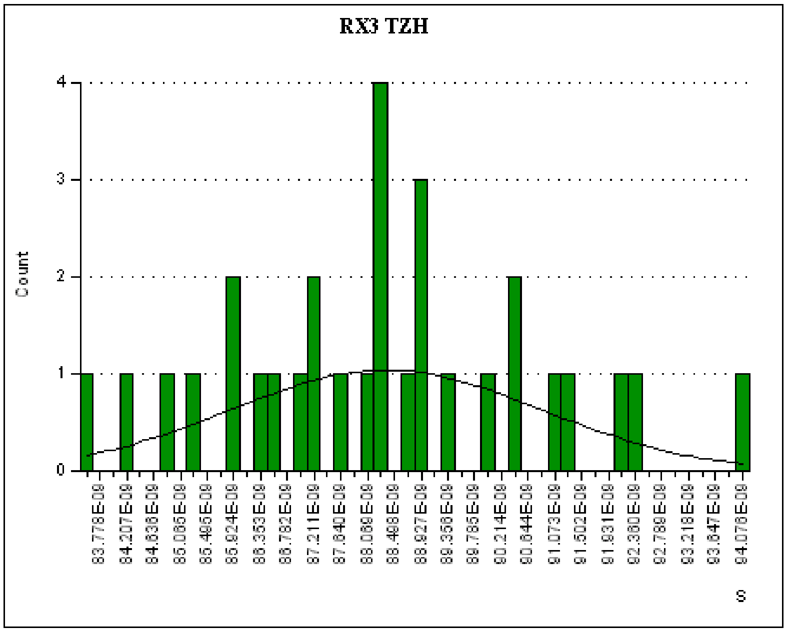
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.002, Test.Name=RX3 TZH



Statistics: (S)

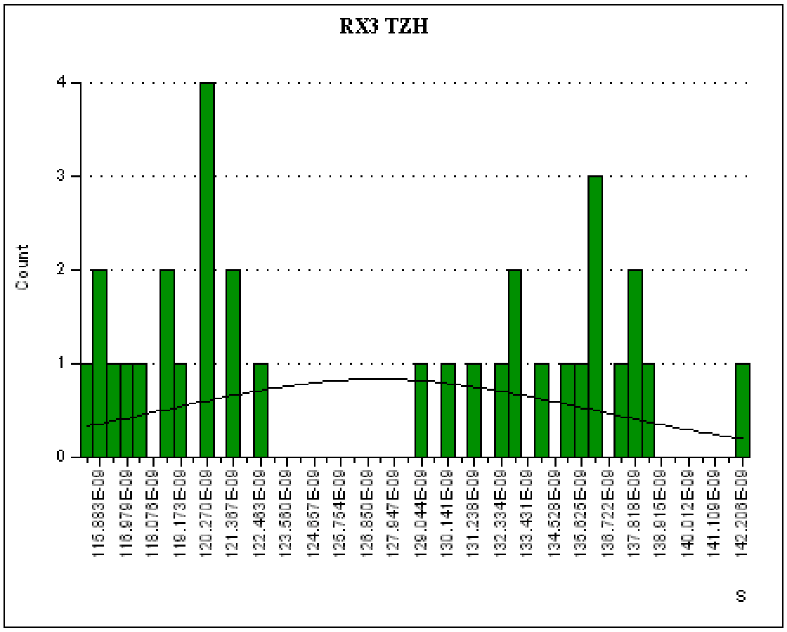
Min	83.564E-09	**Skew**	0.2215
Max	94.076E-09	**StatHigh**	N/A
Mean	88.323E-09	**StatLow**	N/A
StdDev	2.469E-09	**NWithinSpec**	N/A
25%	86.616E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	95.729E-09	**90%**	91.702E-09
		Range	10.513E-09
Mean-3*StdDev	80.916E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.002, Test.Name=RX3 TZH



Statistics: (S)

Min	115.334E-09	**StatLow**	N/A
Max	142.206E-09	**NWithinSpec**	N/A
Mean	127.162E-09	**NOutsideSpec**	N/A
StdDev	8.687E-09	**90%**	137.727E-09
25%	119.124E-09	**Range**	26.872E-09
Mean+3*StdDev	153.224E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	101.101E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0730		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

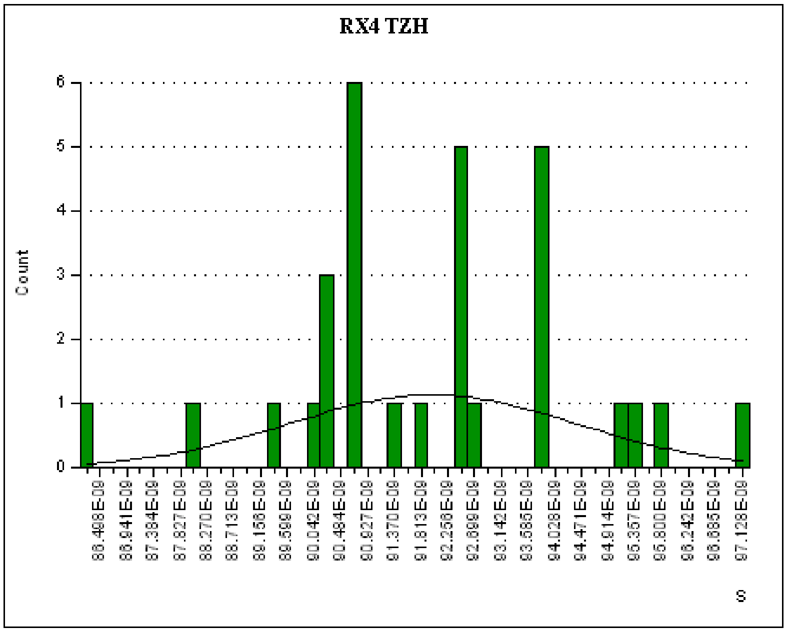
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.003, Test.Name=RX4 TZH



Statistics: (S)

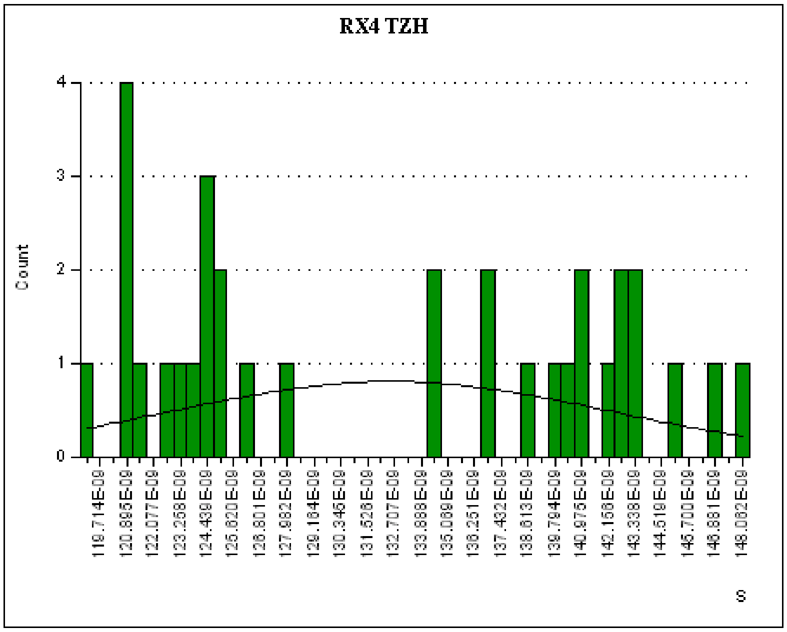
Min	86.277E-09	**Skew**	0.0035
Max	97.128E-09	**StatHigh**	N/A
Mean	91.951E-09	**StatLow**	N/A
StdDev	2.329E-09	**NWithinSpec**	N/A
25%	90.685E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	98.938E-09	**90%**	95.263E-09
		Range	10.852E-09
Mean-3*StdDev	84.964E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.003, Test.Name=RX4 TZH



Statistics: (S)

Min	119.124E-09	**StatLow**	N/A
Max	148.062E-09	**NWithinSpec**	N/A
Mean	132.424E-09	**NOutsideSpec**	N/A
StdDev	9.607E-09	**90%**	143.584E-09
25%	123.947E-09	**Range**	28.939E-09
Mean+3*StdDev	161.246E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	103.602E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.1009		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

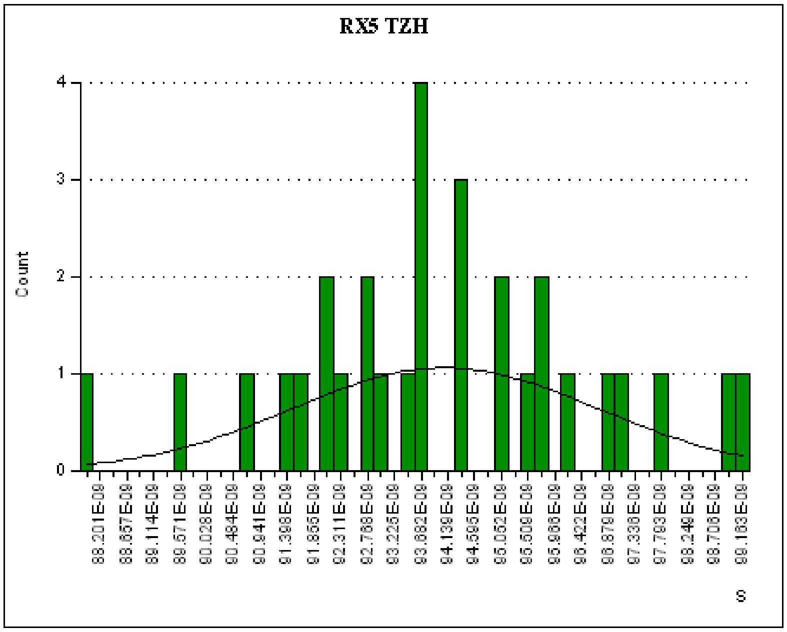
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.004, Test.Name=RX5 TZH



Statistics: (S)

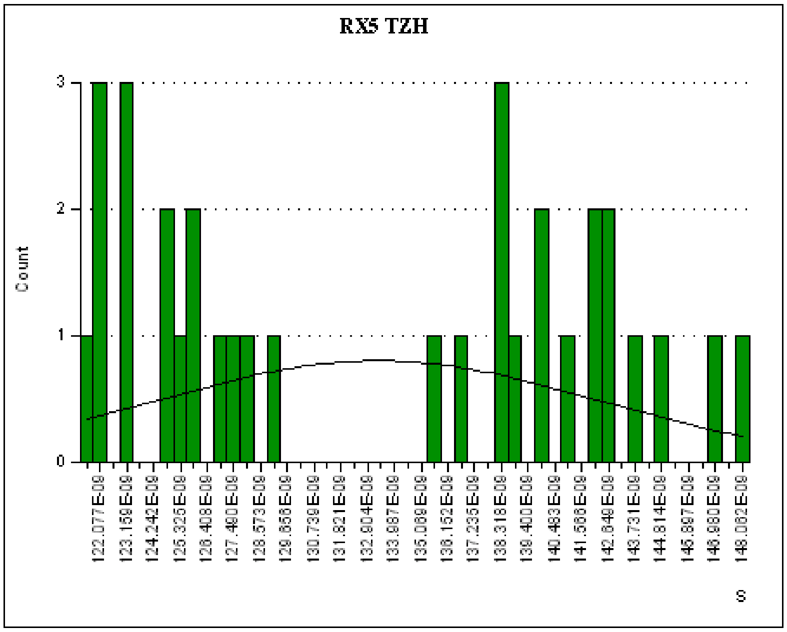
Min	87.972E-09	**Skew**	-0.0567
Max	99.163E-09	**StatHigh**	N/A
Mean	94.031E-09	**StatLow**	N/A
StdDev	2.567E-09	**NWithinSpec**	N/A
25%	92.381E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	101.731E-09	**90%**	97.467E-09
Mean-3*StdDev	86.331E-09	**Range**	11.191E-09
Cpk	N/A	**NOutsideSpec**	N/A

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.004, Test.Name=RX5 TZH



Statistics: (S)

Min	121.535E-09	**StatLow**	N/A
Max	148.062E-09	**NWithinSpec**	N/A
Mean	133.196E-09	**NOutsideSpec**	N/A
StdDev	8.871E-09	**90%**	143.928E-09
25%	124.980E-09	**Range**	26.527E-09
Mean+3*StdDev	159.808E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	106.584E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.0792		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

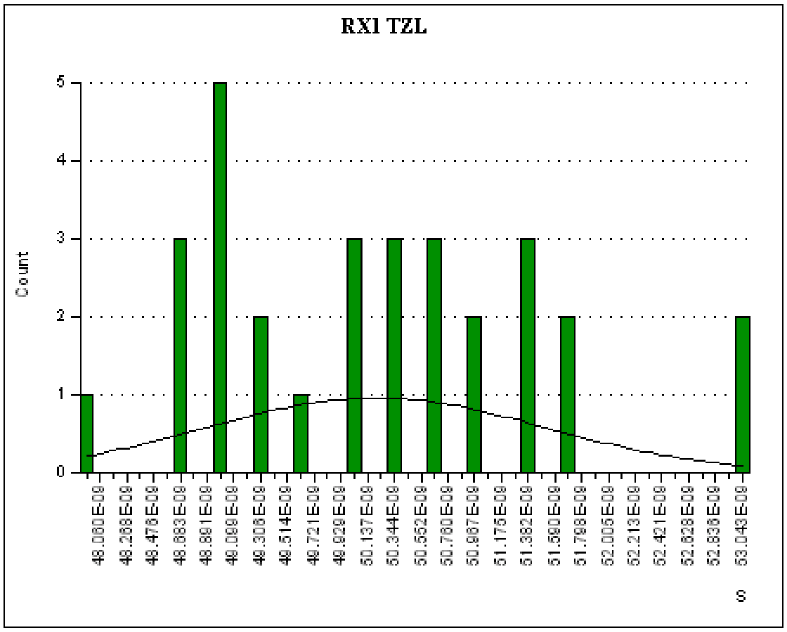
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.005, Test.Name=RX1 TZL



Statistics: (S)

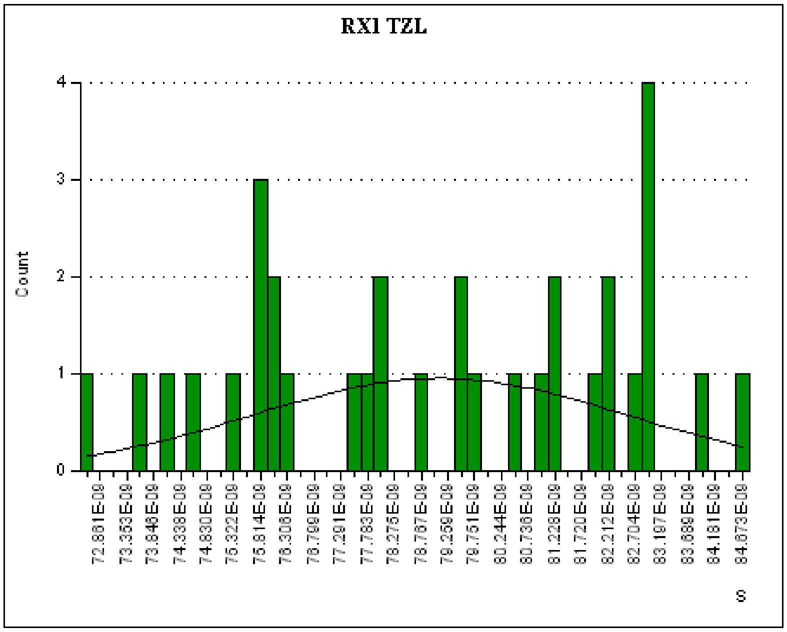
Min	47.957E-09	**Skew**	0.4664
Max	53.043E-09	**StatHigh**	N/A
Mean	50.184E-09	**StatLow**	N/A
StdDev	1.293E-09	**NWithinSpec**	N/A
25%	48.974E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	54.061E-09	**90%**	51.687E-09
		Range	5.087E-09
Mean-3*StdDev	46.306E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.005, Test.Name=RX1 TZL



Statistics: (S)

Min	72.615E-09	**StatLow**	N/A
Max	84.673E-09	**NWithinSpec**	N/A
Mean	79.046E-09	**NOutsideSpec**	N/A
StdDev	3.388E-09	**90%**	82.950E-09
25%	76.060E-09	**Range**	12.058E-09
Mean+3*StdDev	89.211E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	68.881E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.1472		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

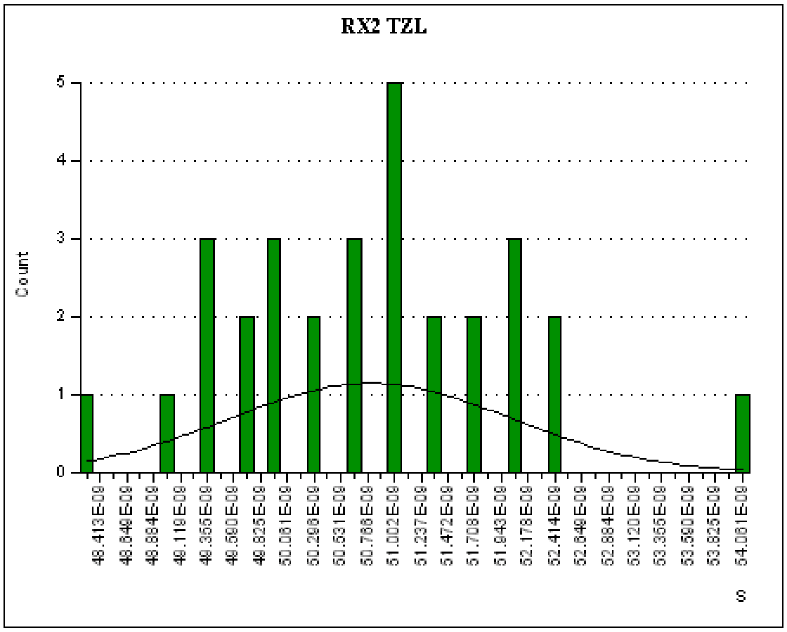
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.006, Test.Name=RX2 TZL



Statistics: (S)

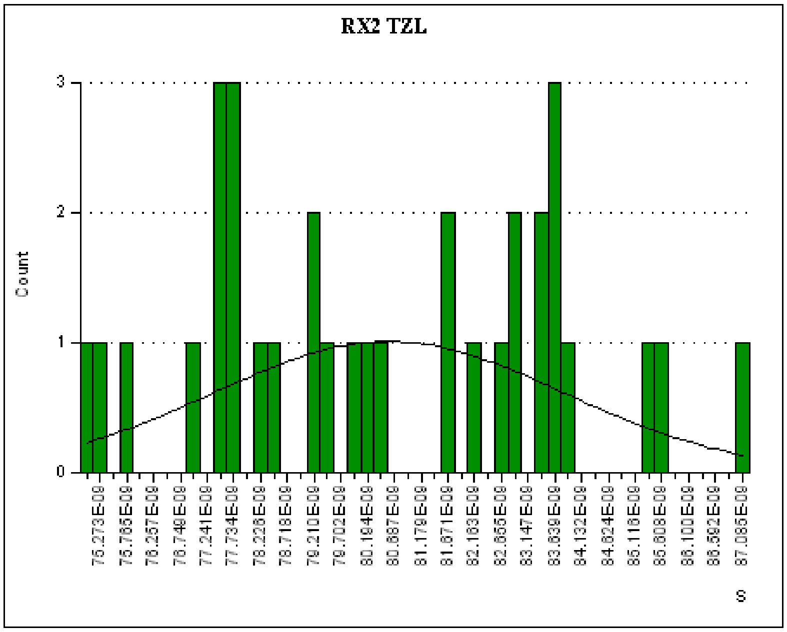
Min	48.296E-09	**Skew**	0.3376
Max	54.061E-09	**StatHigh**	N/A
Mean	50.771E-09	**StatLow**	N/A
StdDev	1.228E-09	**NWithinSpec**	N/A
25%	49.991E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	54.455E-09	**90%**	52.196E-09
		Range	5.765E-09
Mean-3*StdDev	47.087E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.006, Test.Name=RX2 TZL



Statistics: (S)

Min	75.027E-09	**StatLow**	N/A
Max	87.085E-09	**NWithinSpec**	N/A
Mean	80.528E-09	**NOutsideSpec**	N/A
StdDev	3.207E-09	**90%**	83.984E-09
25%	77.783E-09	**Range**	12.058E-09
Mean+3*StdDev	90.149E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	70.908E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.1180		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

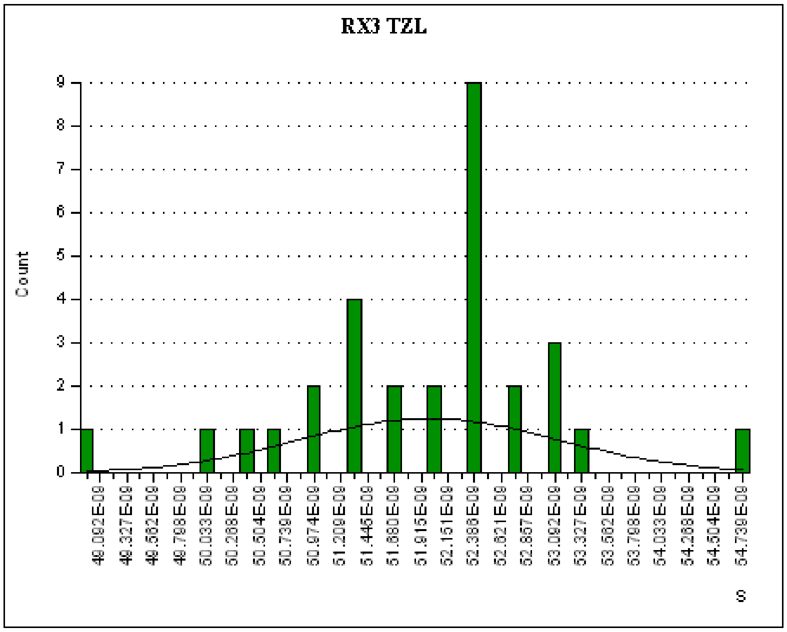
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.007, Test.Name=RX3 TZL



Statistics: (S)

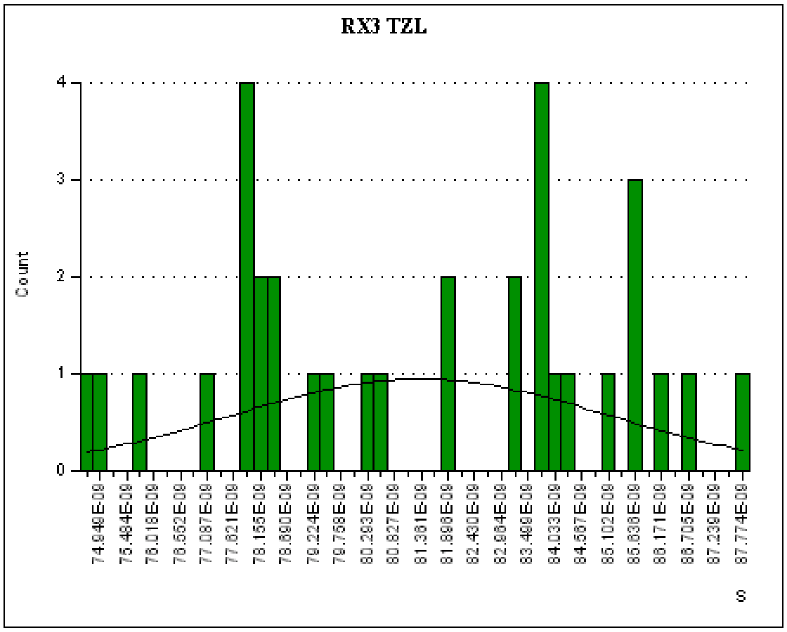
Min	48.974E-09	**Skew**	-0.3578
Max	54.739E-09	**StatHigh**	N/A
Mean	51.958E-09	**StatLow**	N/A
StdDev	1.121E-09	**NWithinSpec**	N/A
25%	51.348E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	55.321E-09	**90%**	53.043E-09
		Range	5.765E-09
Mean-3*StdDev	48.596E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.007, Test.Name=RX3 TZL



Statistics: (S)

Min	74.682E-09	**StatLow**	N/A
Max	87.774E-09	**NWithinSpec**	N/A
Mean	81.280E-09	**NOutsideSpec**	N/A
StdDev	3.710E-09	**90%**	85.707E-09
25%	78.127E-09	**Range**	13.091E-09
Mean+3*StdDev	92.409E-09	**NOutsideSpec**	N/A
Mean-3*StdDev	70.151E-09	**Cp**	N/A
Cpk	N/A	**Cpl**	N/A
Skew	-0.0634	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

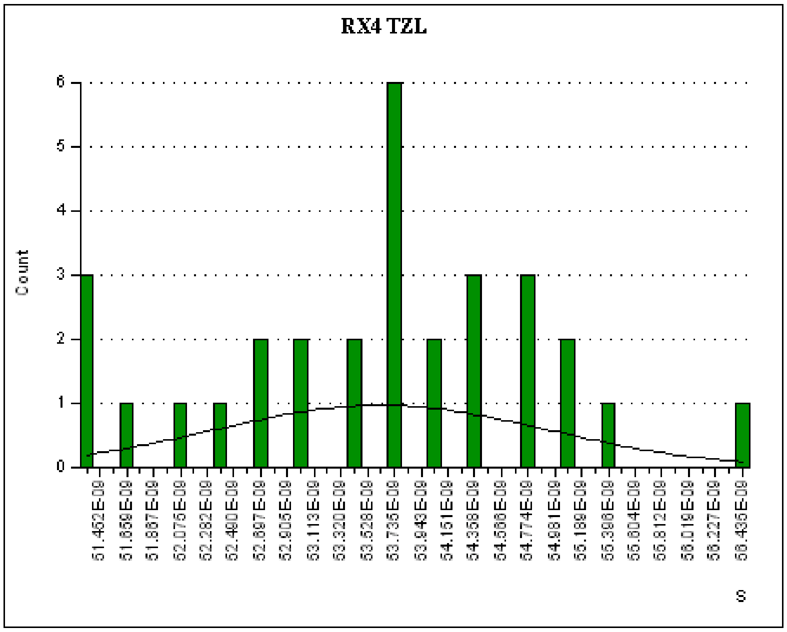
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.008, Test.Name=RX4 TZL



Statistics: (S)

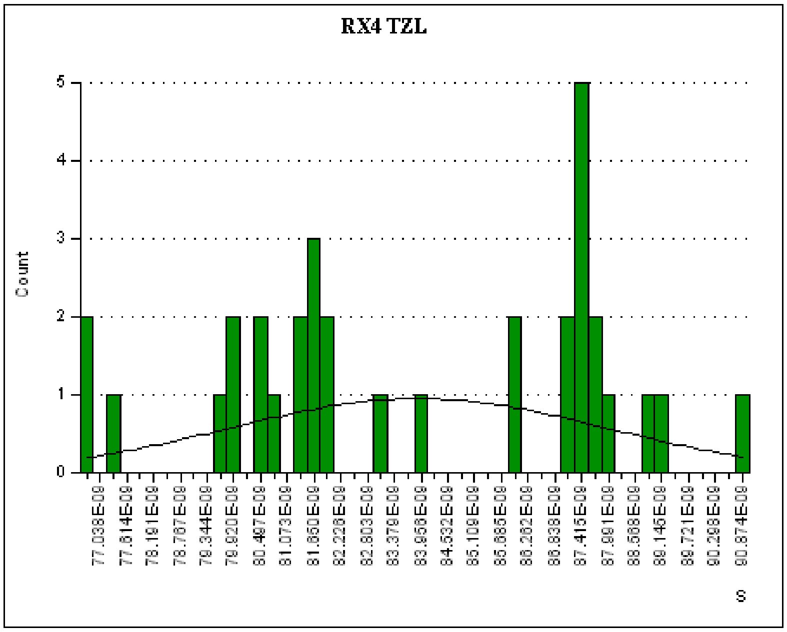
Min	51.348E-09	**Skew**	-0.1541
Max	56.435E-09	**StatHigh**	N/A
Mean	53.609E-09	**StatLow**	N/A
StdDev	1.276E-09	**NWithinSpec**	N/A
25%	52.704E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	57.437E-09	**90%**	55.078E-09
		Range	5.087E-09
Mean-3*StdDev	49.780E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.008, Test.Name=RX4 TZL



Statistics: (S)

Min	76.749E-09	**StatLow**	N/A
Max	90.874E-09	**NWithinSpec**	N/A
Mean	83.817E-09	**NOutsideSpec**	N/A
StdDev	3.980E-09	**90%**	88.118E-09
25%	80.883E-09	**Range**	14.125E-09
Mean+3*StdDev	95.756E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	71.878E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.1006		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

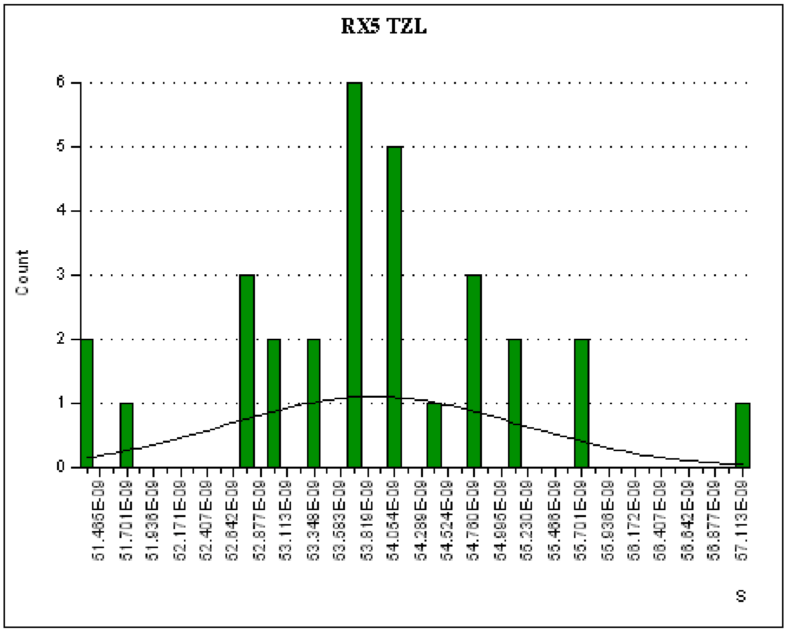
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.009, Test.Name=RX5 TZL



Statistics: (S)

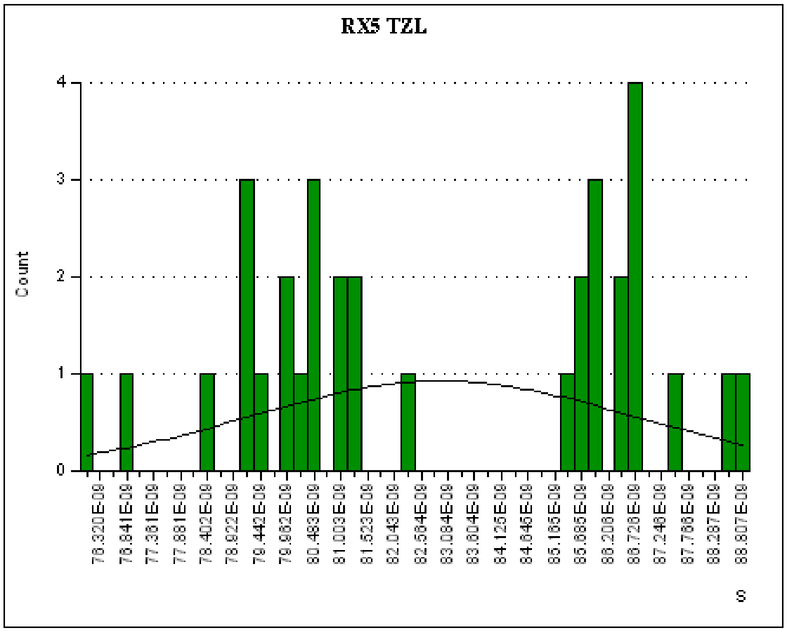
Min	51.348E-09	**Skew**	0.1433
Max	57.113E-09	**StatHigh**	N/A
Mean	53.846E-09	**StatLow**	N/A
StdDev	1.270E-09	**NWithinSpec**	N/A
25%	53.043E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	57.657E-09	**90%**	55.417E-09
		Range	5.765E-09
Mean-3*StdDev	50.035E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.009, Test.Name=RX5 TZL



Statistics: (S)

Min	76.060E-09	**StatLow**	N/A
Max	88.807E-09	**NWithinSpec**	N/A
Mean	82.898E-09	**NOutsideSpec**	N/A
StdDev	3.691E-09	**90%**	86.740E-09
25%	79.850E-09	**Range**	12.747E-09
Mean+3*StdDev	93.970E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	71.827E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0259		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

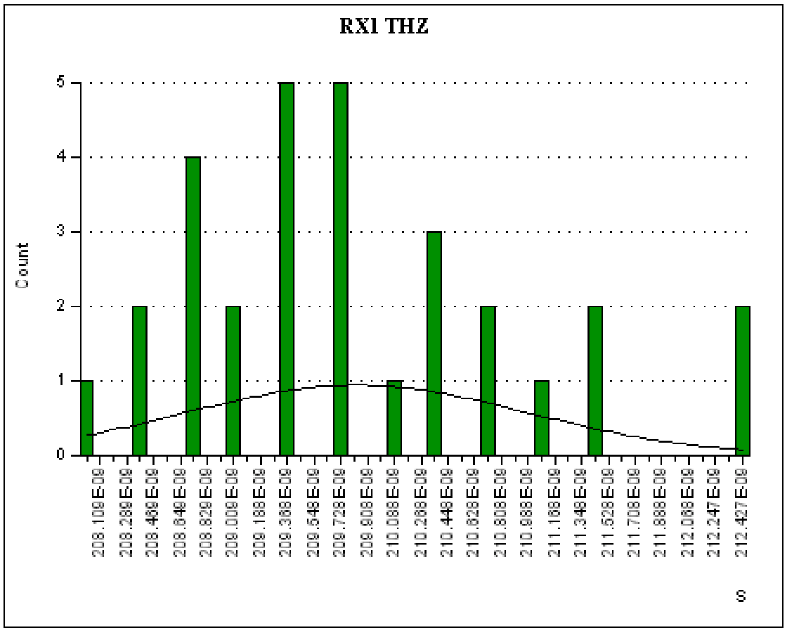
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.010, Test.Name=RX1 THZ



Statistics: (S)

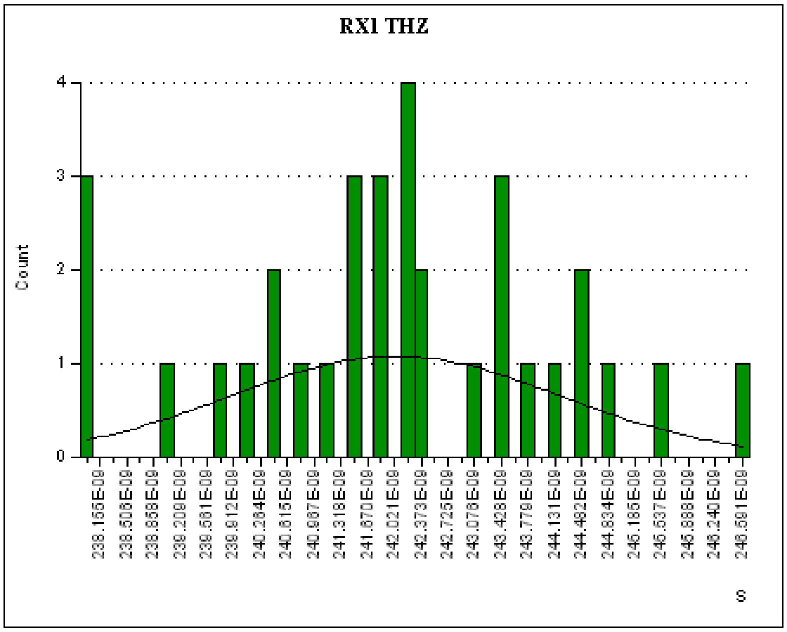
Min	208.019E-09	**Skew**	0.7165
Max	212.427E-09	**StatHigh**	N/A
Mean	209.816E-09	**StatLow**	N/A
StdDev	1.141E-09	**NWithinSpec**	N/A
25%	209.036E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	213.239E-09	**90%**	211.410E-09
		Range	4.408E-09
Mean-3*StdDev	206.393E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.010, Test.Name=RX1 THZ



Statistics: (S)

Min	237.979E-09	**StatLow**	N/A
Max	246.591E-09	**NWithinSpec**	N/A
Mean	241.998E-09	**NOutsideSpec**	N/A
StdDev	2.140E-09	**90%**	244.524E-09
25%	240.735E-09	**Range**	8.613E-09
Mean+3*StdDev	248.420E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	235.577E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0896		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

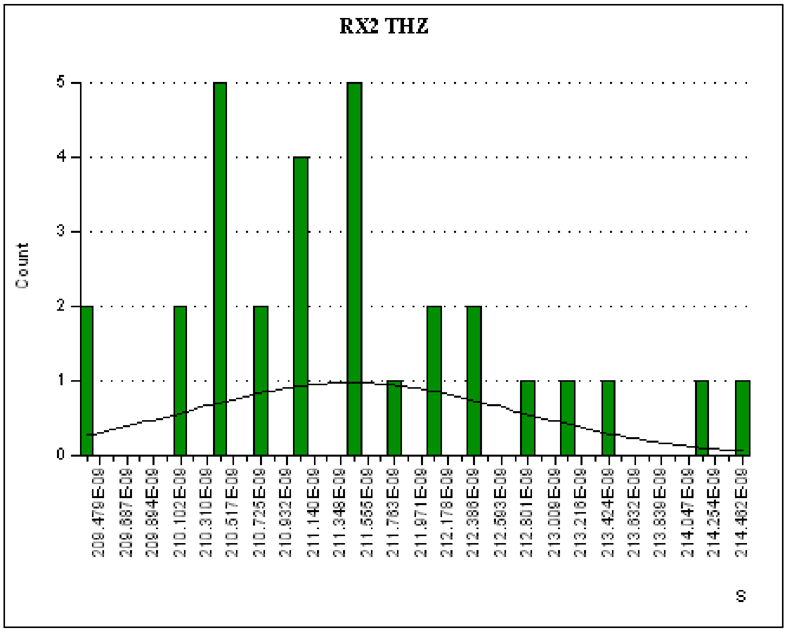
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:26 PM

Test.Number=19.011, Test.Name=RX2 THZ



Statistics: (S)

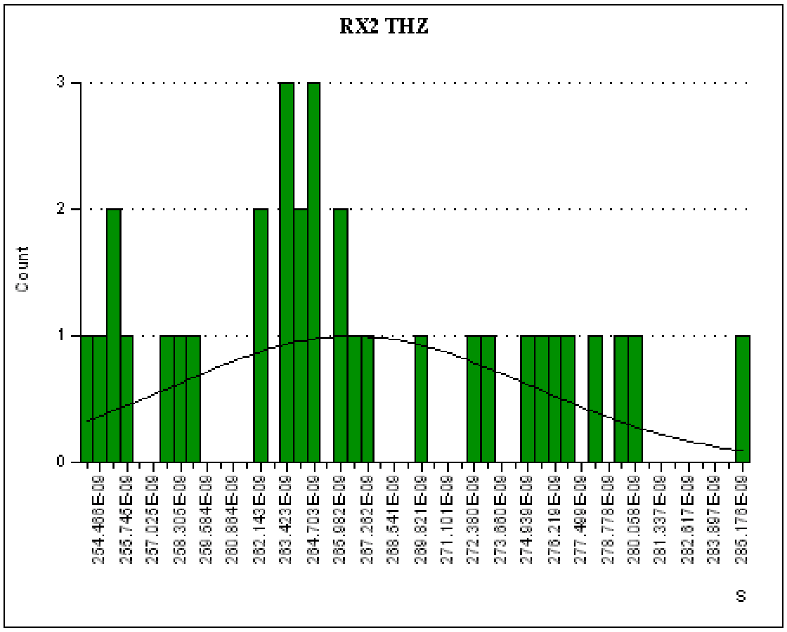
Min	209.375E-09	**Skew**	0.6964
Max	214.462E-09	**StatHigh**	N/A
Mean	211.410E-09	**StatLow**	N/A
StdDev	1.275E-09	**NWithinSpec**	N/A
25%	210.393E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	215.235E-09	**90%**	213.275E-09
		Range	5.087E-09
Mean-3*StdDev	207.585E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.011, Test.Name=RX2 THZ



Statistics: (S)

Min	253.826E-09	**StatLow**	N/A
Max	285.176E-09	**NWithinSpec**	N/A
Mean	266.406E-09	**NOutsideSpec**	N/A
StdDev	8.440E-09	**90%**	278.286E-09
25%	262.094E-09	**Range**	31.350E-09
Mean+3*StdDev	291.725E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	241.087E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3915		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

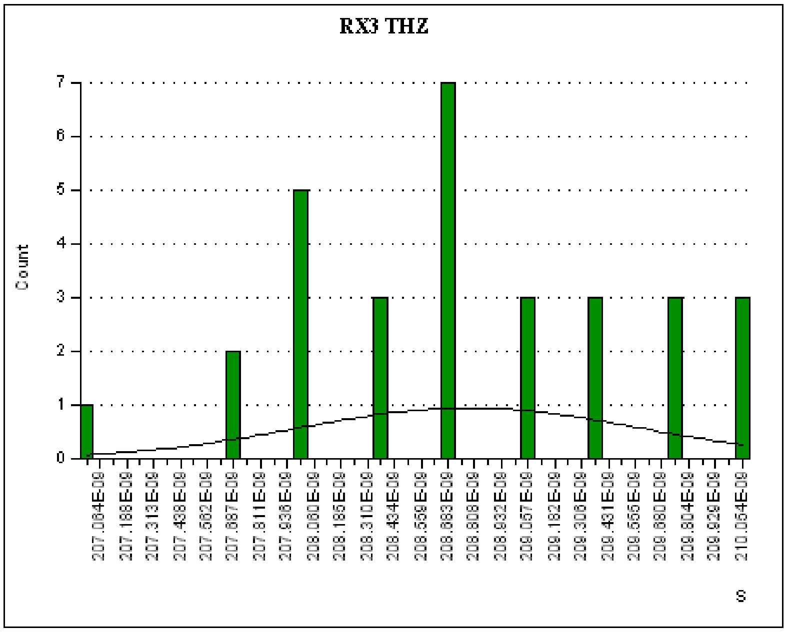
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=19.012, Test.Name=RX3 THZ



Statistics: (S)

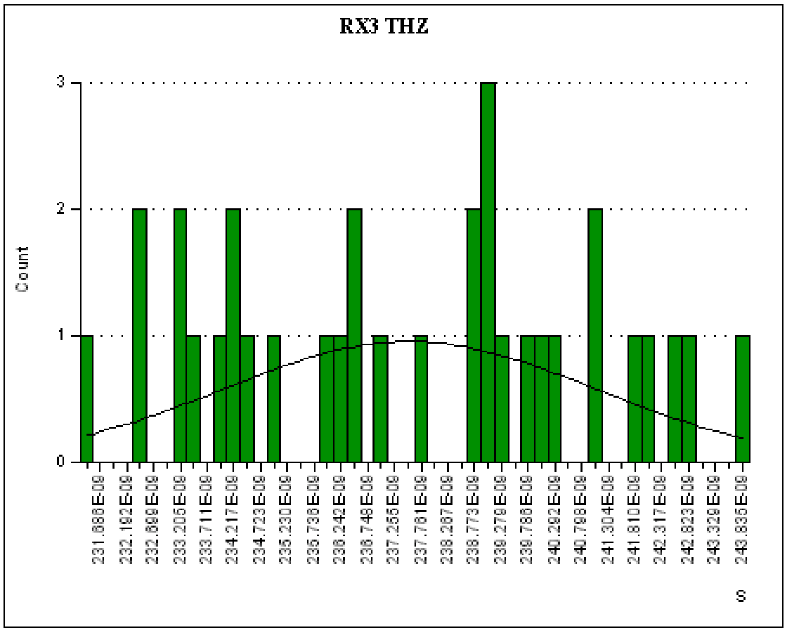
Min	207.002E-09	**Skew**	-0.0453
Max	210.054E-09	**StatHigh**	N/A
Mean	208.765E-09	**StatLow**	N/A
StdDev	783.488E-12	**NWithinSpec**	N/A
25%	208.019E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	211.115E-09	**90%**	209.884E-09
		Range	3.052E-09
Mean-3*StdDev	206.414E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.012, Test.Name=RX3 THZ



Statistics: (S)

Min	231.433E-09	**StatLow**	N/A
Max	243.835E-09	**NWithinSpec**	N/A
Mean	237.478E-09	**NOutsideSpec**	N/A
StdDev	3.486E-09	**90%**	242.113E-09
25%	234.189E-09	**Range**	12.402E-09
Mean+3*StdDev	247.935E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	227.020E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.0084		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

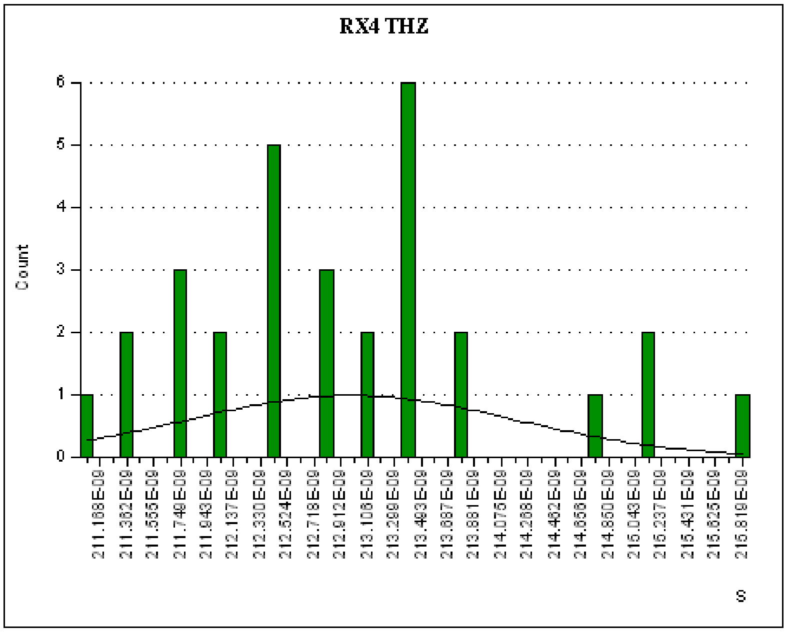
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=19.013, Test.Name=RX4 THZ



Statistics: (S)

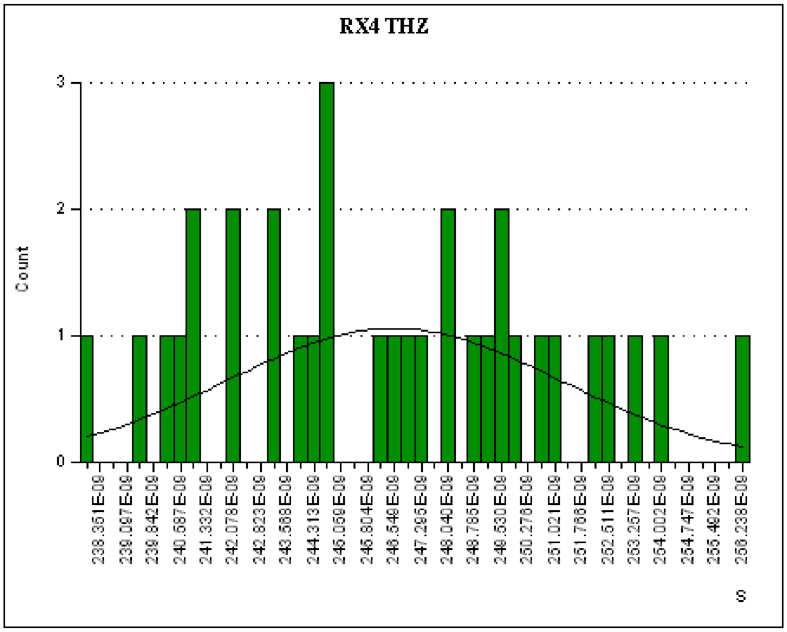
Min	211.071E-09	**Skew**	0.6767
Max	215.819E-09	**StatHigh**	N/A
Mean	212.970E-09	**StatLow**	N/A
StdDev	1.170E-09	**NWithinSpec**	N/A
25%	212.088E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	216.480E-09	**90%**	214.971E-09
		Range	4.748E-09
Mean-3*StdDev	209.460E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.013, Test.Name=RX4 THZ



Statistics: (S)

Min	237.979E-09	**StatLow**	N/A
Max	256.238E-09	**NWithinSpec**	N/A
Mean	246.445E-09	**NOutsideSpec**	N/A
StdDev	4.633E-09	**90%**	252.448E-09
25%	243.146E-09	**Range**	18.259E-09
Mean+3*StdDev	260.345E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	232.545E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.1226		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

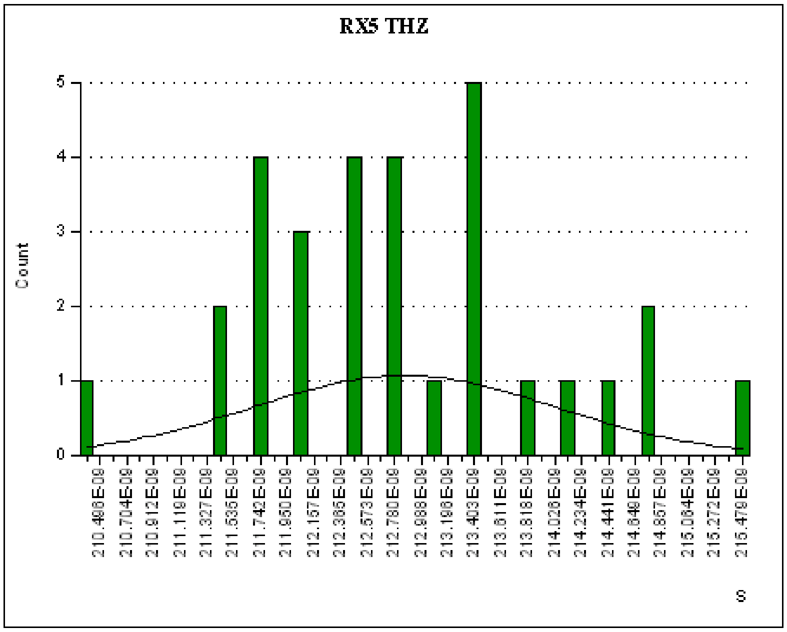
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=19.014, Test.Name=RX5 THZ



Statistics: (S)

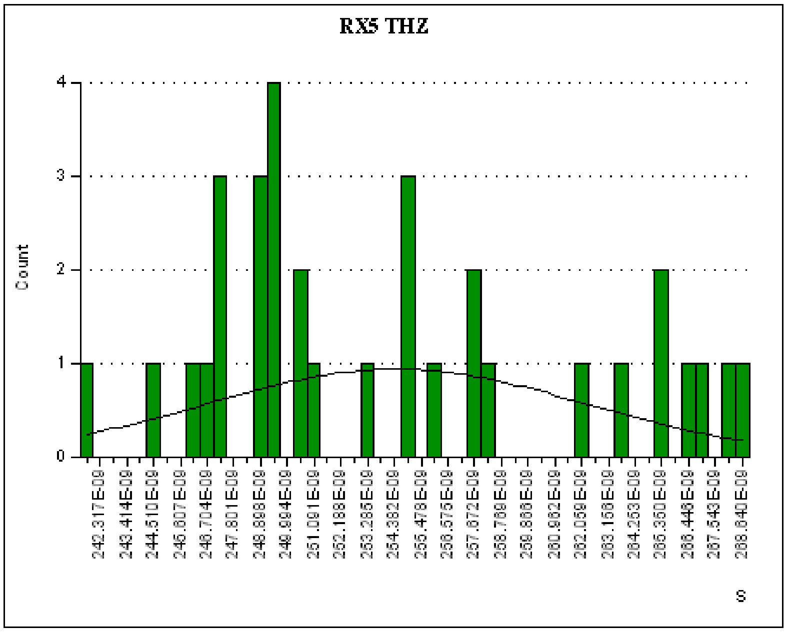
Min	210.393E-09	**Skew**	0.3613
Max	215.479E-09	**StatHigh**	N/A
Mean	212.834E-09	**StatLow**	N/A
StdDev	1.159E-09	**NWithinSpec**	N/A
25%	212.088E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	216.312E-09	**90%**	214.632E-09
		Range	5.087E-09
Mean-3*StdDev	209.357E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.014, Test.Name=RX5 THZ



Statistics: (S)

Min	241.768E-09	**StatLow**	N/A
Max	268.640E-09	**NWithinSpec**	N/A
Mean	254.338E-09	**NOutsideSpec**	N/A
StdDev	7.665E-09	**90%**	266.573E-09
25%	249.003E-09	**Range**	26.872E-09
Mean+3*StdDev	277.334E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	231.342E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.5527		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

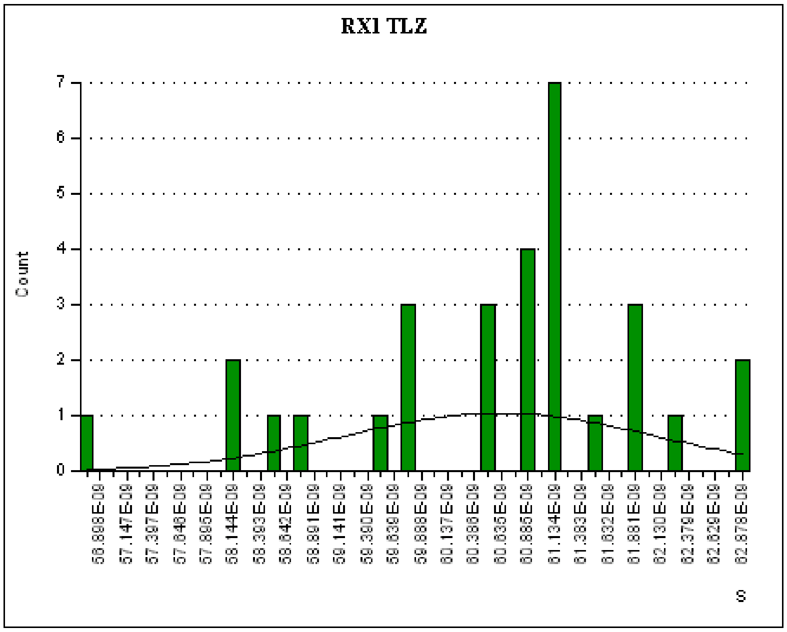
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=19.015, Test.Name=RX1 TLZ



Statistics: (S)

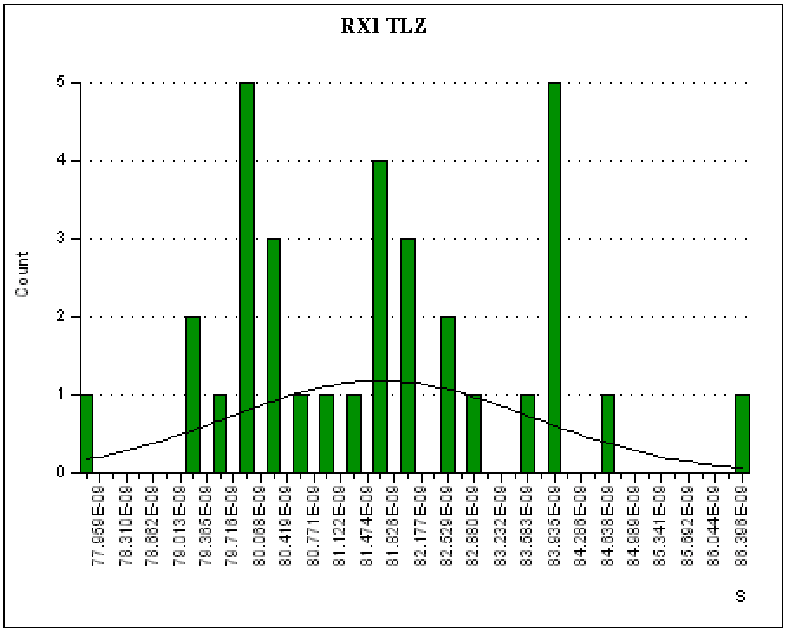
Min	56.774E-09	**Skew**	-0.8369
Max	62.878E-09	**StatHigh**	N/A
Mean	60.583E-09	**StatLow**	N/A
StdDev	1.424E-09	**NWithinSpec**	N/A
25%	59.826E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	64.855E-09	**90%**	62.030E-09
		Range	6.104E-09
Mean-3*StdDev	56.311E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.015, Test.Name=RX1 TLZ



Statistics: (S)

Min	77.783E-09	**StatLow**	N/A
Max	86.396E-09	**NWithinSpec**	N/A
Mean	81.604E-09	**NOutsideSpec**	N/A
StdDev	1.961E-09	**90%**	83.984E-09
25%	79.850E-09	**Range**	8.613E-09
Mean+3*StdDev	87.486E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	75.721E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3890		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

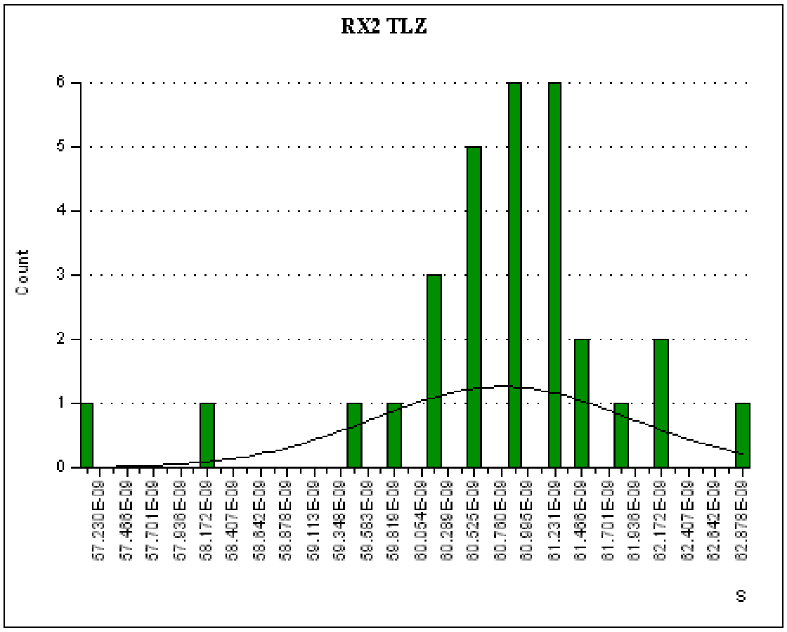
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=19.016, Test.Name=RX2 TLZ



Statistics: (S)

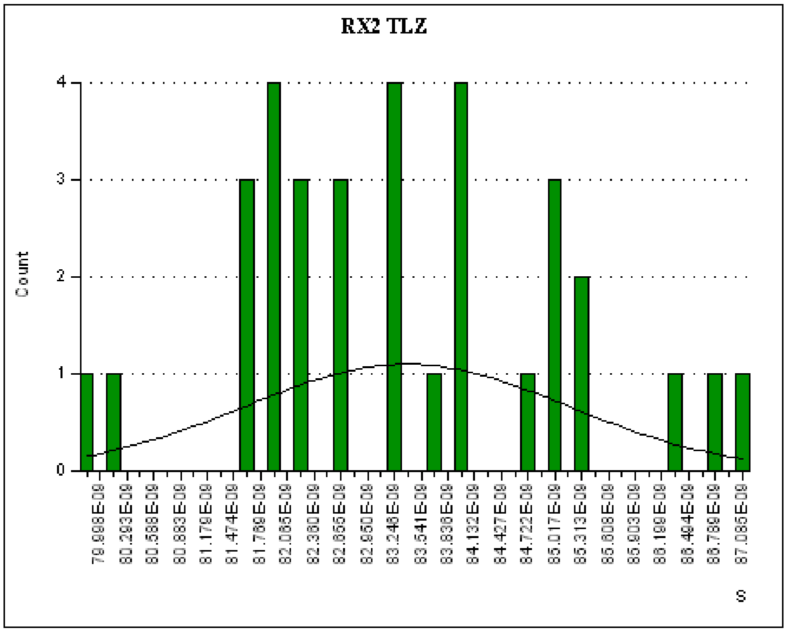
Min	57.113E-09	**Skew**	-1.2965
Max	62.878E-09	**StatHigh**	N/A
Mean	60.730E-09	**StatLow**	N/A
StdDev	1.117E-09	**NWithinSpec**	N/A
25%	60.504E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	64.081E-09	**90%**	62.030E-09
		Range	5.765E-09
Mean-3*StdDev	57.379E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.016, Test.Name=RX2 TLZ



Statistics: (S)

Min	79.850E-09	**StatLow**	N/A
Max	87.085E-09	**NWithinSpec**	N/A
Mean	83.347E-09	**NOutsideSpec**	N/A
StdDev	1.765E-09	**90%**	85.362E-09
25%	81.917E-09	**Range**	7.235E-09
Mean+3*StdDev	88.643E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	78.051E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2762		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

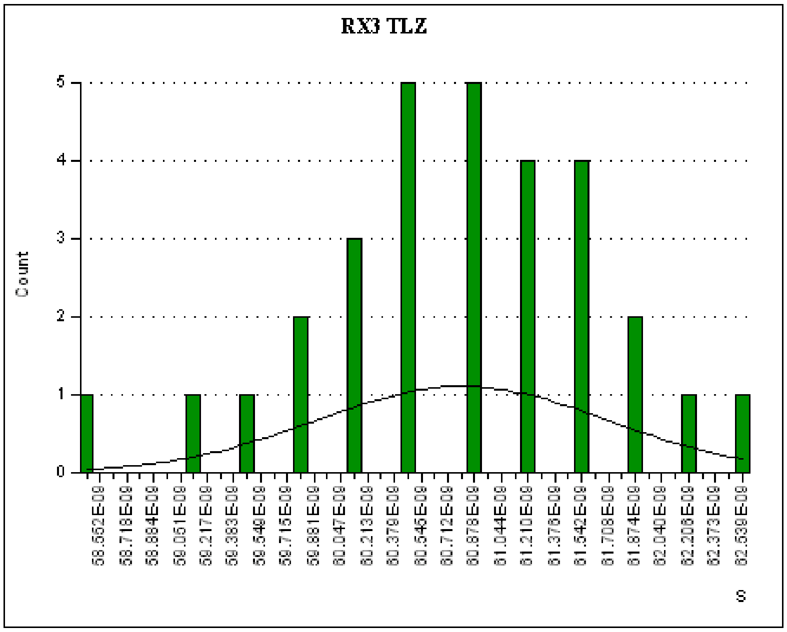
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=19.017, Test.Name=RX3 TLZ



Statistics: (S)

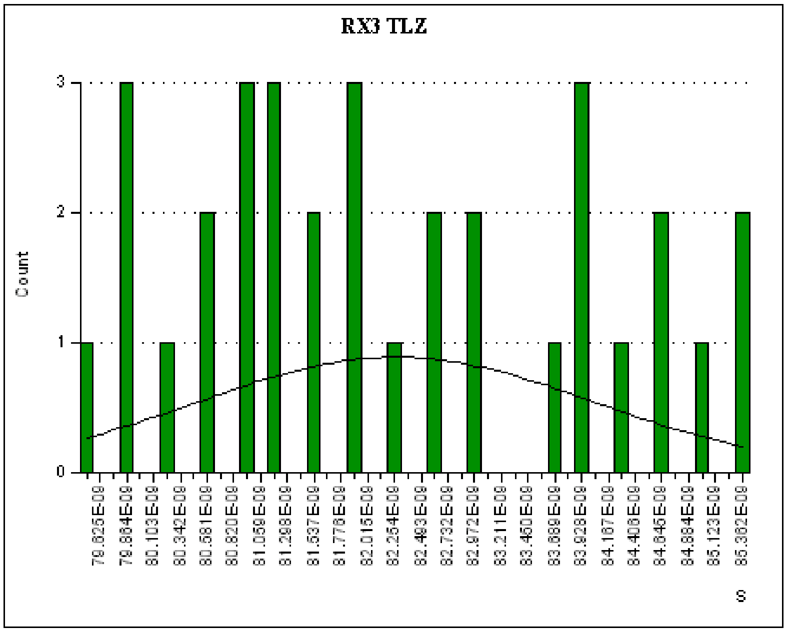
Min	58.469E-09	**Skew**	-0.4277
Max	62.539E-09	**StatHigh**	N/A
Mean	60.775E-09	**StatLow**	N/A
StdDev	896.768E-12	**NWithinSpec**	N/A
25%	60.165E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	63.465E-09	**90%**	61.860E-09
		Range	4.069E-09
Mean-3*StdDev	58.085E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.017, Test.Name=RX3 TLZ



Statistics: (S)

Min	79.505E-09	**StatLow**	N/A
Max	85.362E-09	**NWithinSpec**	N/A
Mean	82.241E-09	**NOutsideSpec**	N/A
StdDev	1.769E-09	**90%**	84.673E-09
25%	80.883E-09	**Range**	5.857E-09
Mean+3*StdDev	87.548E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	76.933E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2907		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

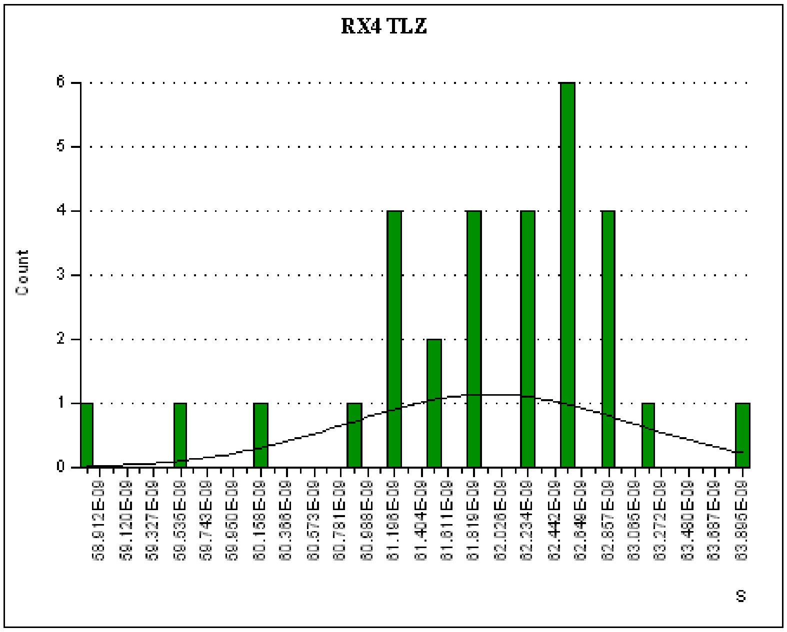
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=19.018, Test.Name=RX4 TLZ



Statistics: (S)

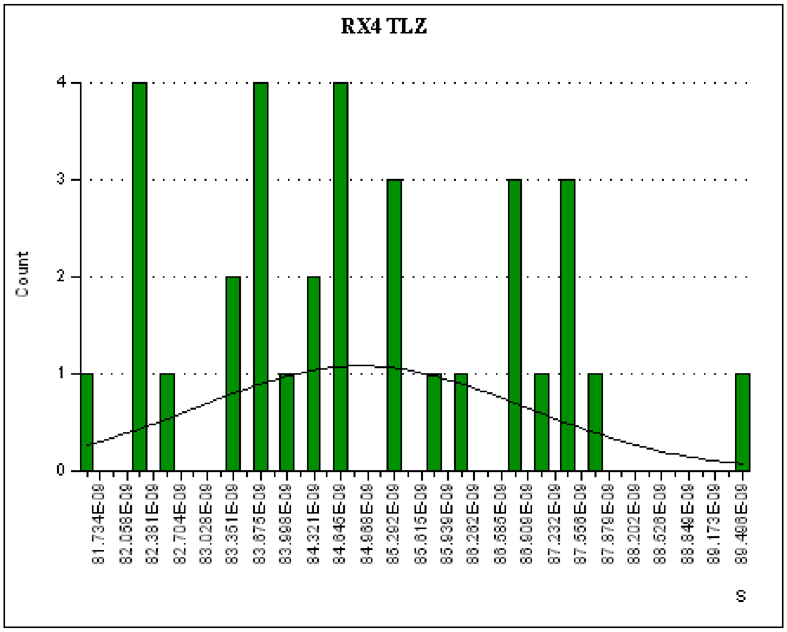
Min	58.808E-09	**Skew**	-1.0538
Max	63.895E-09	**StatHigh**	N/A
Mean	61.906E-09	**StatLow**	N/A
StdDev	1.086E-09	**NWithinSpec**	N/A
25%	61.182E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	65.164E-09	**90%**	62.878E-09
		Range	5.087E-09
Mean-3*StdDev	58.647E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.018, Test.Name=RX4 TLZ



Statistics: (S)

Min	81.572E-09	**StatLow**	N/A
Max	89.496E-09	**NWithinSpec**	N/A
Mean	84.861E-09	**NOutsideSpec**	N/A
StdDev	1.964E-09	**90%**	87.429E-09
25%	83.639E-09	**Range**	7.924E-09
Mean+3*StdDev	90.753E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	78.968E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3311		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

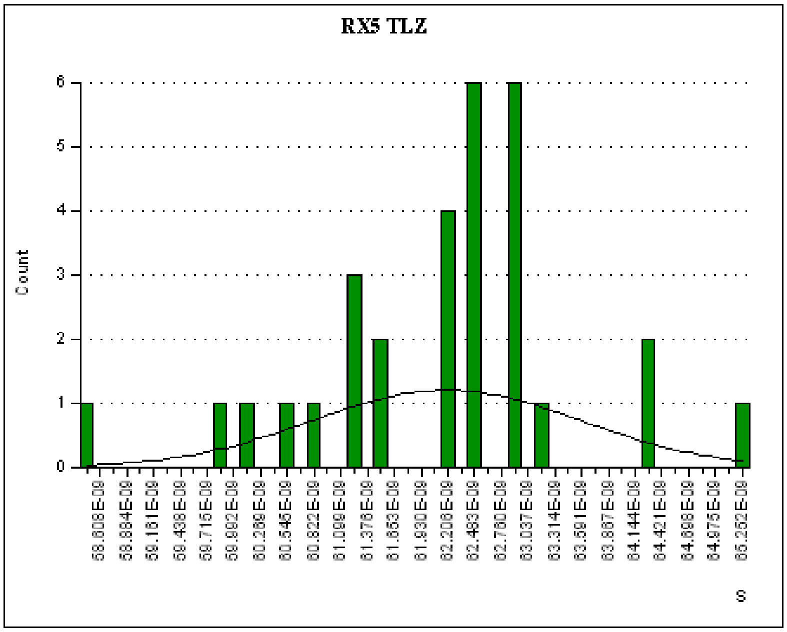
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=19.019, Test.Name=RX5 TLZ



Statistics: (S)

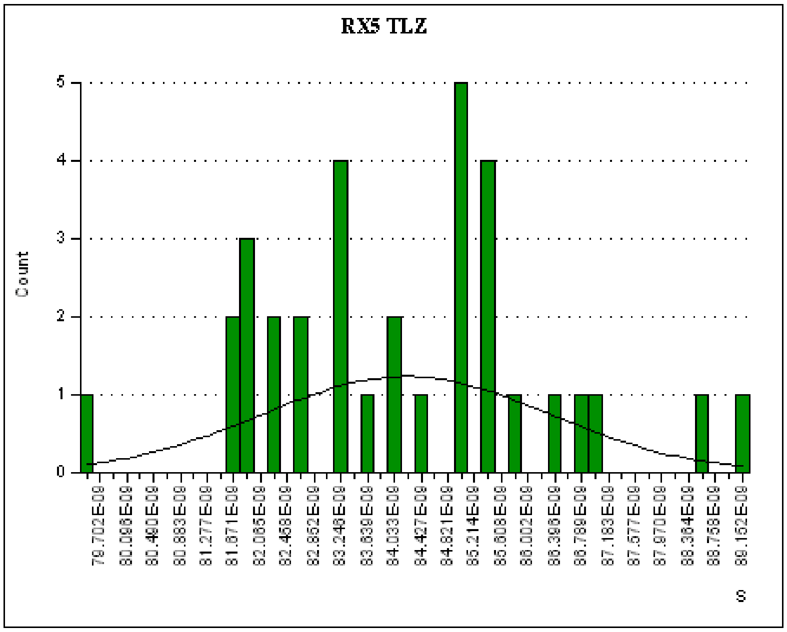
Min	58.469E-09	**Skew**	-0.4170
Max	65.252E-09	**StatHigh**	N/A
Mean	62.154E-09	**StatLow**	N/A
StdDev	1.370E-09	**NWithinSpec**	N/A
25%	61.182E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	66.265E-09	**90%**	63.725E-09
		Range	6.782E-09
Mean-3*StdDev	58.044E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.019, Test.Name=RX5 TLZ



Statistics: (S)

Min	79.505E-09	**StatLow**	N/A
Max	89.152E-09	**NWithinSpec**	N/A
Mean	84.161E-09	**NOutsideSpec**	N/A
StdDev	2.099E-09	**90%**	86.740E-09
25%	82.606E-09	**Range**	9.646E-09
Mean+3*StdDev	90.459E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	77.864E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2779		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

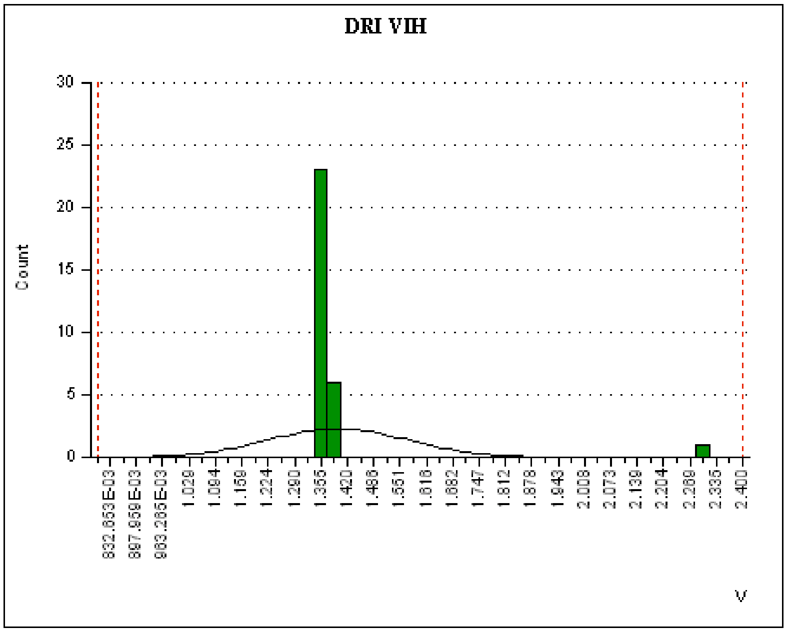
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=20.000, Test.Name=DRI VIH



Statistics: (V)

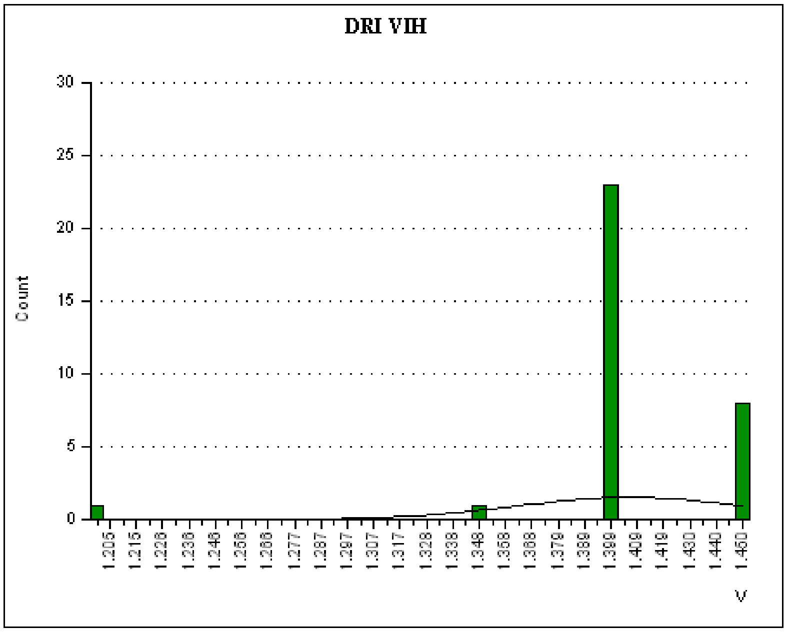
Min	1.350	**Skew**	5.3592
Max	2.300	**StatHigh**	N/A
Mean	1.392	**StatLow**	N/A
StdDev	172.748E-03	**NWithinSpec**	30
25%	1.350	**NOutsideSpec**	0
Mean+3*StdDev	1.910	**90%**	1.400
		Range	950.000E-03
Mean-3*StdDev	873.422E-03	**NOutsideSpec**	0
Cpk	1.1417		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.000, Test.Name=DRI VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.450	**NWithinSpec**	N/A
Mean	1.405	**NOutsideSpec**	N/A
StdDev	43.952E-03	**90%**	1.450
25%	1.400	**Range**	250.000E-03
Mean+3*StdDev	1.536	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.273	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-3.1230		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

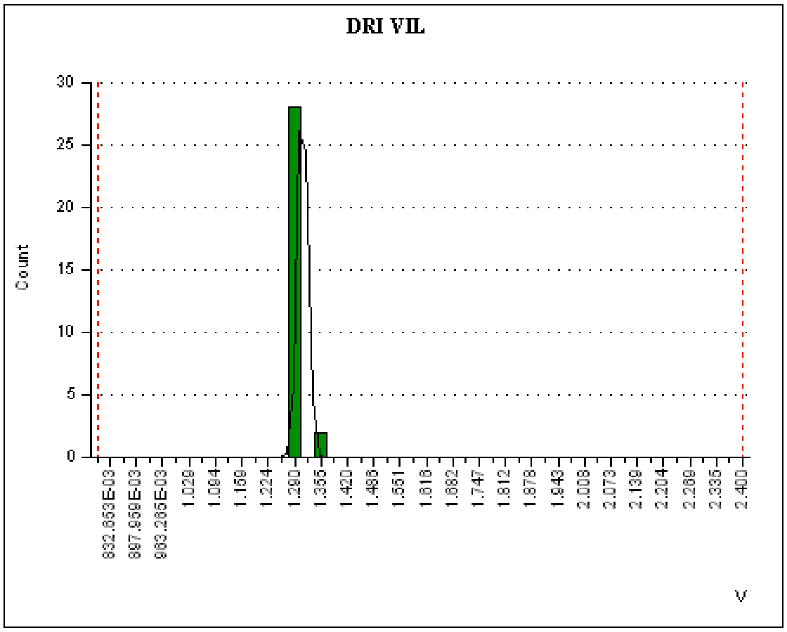
Conditions

Vcc	**temp**
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=20.001, Test.Name=DRI VIL



Statistics: (V)

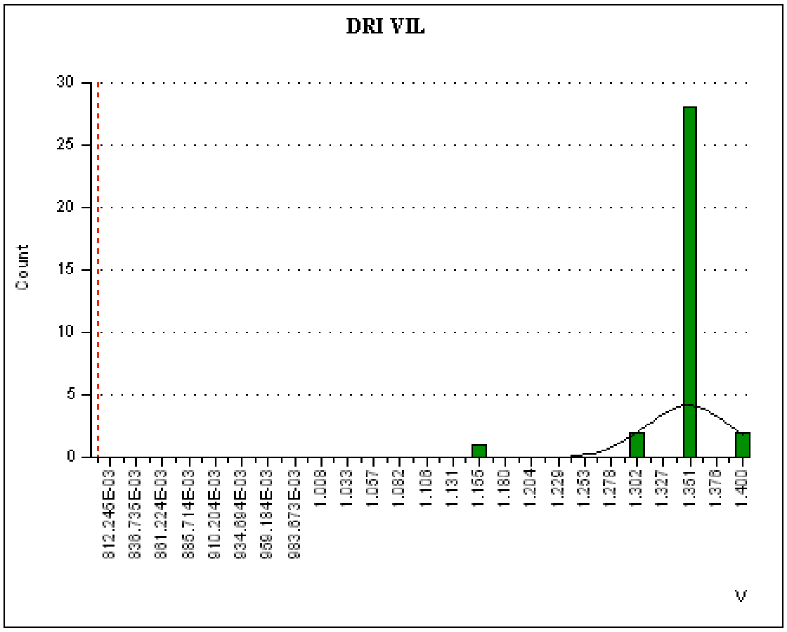
Min	1.300	**Skew**	3.6600
Max	1.350	**StatHigh**	N/A
Mean	1.303	**StatLow**	N/A
StdDev	12.685E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.341	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.265	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.001, Test.Name=DRI VIL



Statistics: (V)

Min	1.150	**StatLow**	N/A
Max	1.400	**NWithinSpec**	33
Mean	1.344	**NOutsideSpec**	0
StdDev	39.046E-03	**90%**	1.350
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.461	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.227	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-3.9707		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

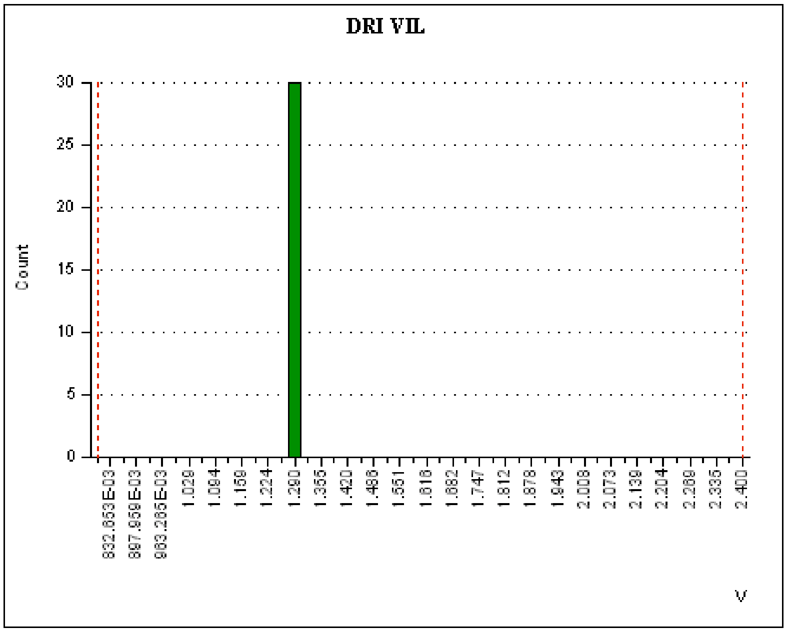
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=20.003, Test.Name=DRI VIL



Statistics: (V)

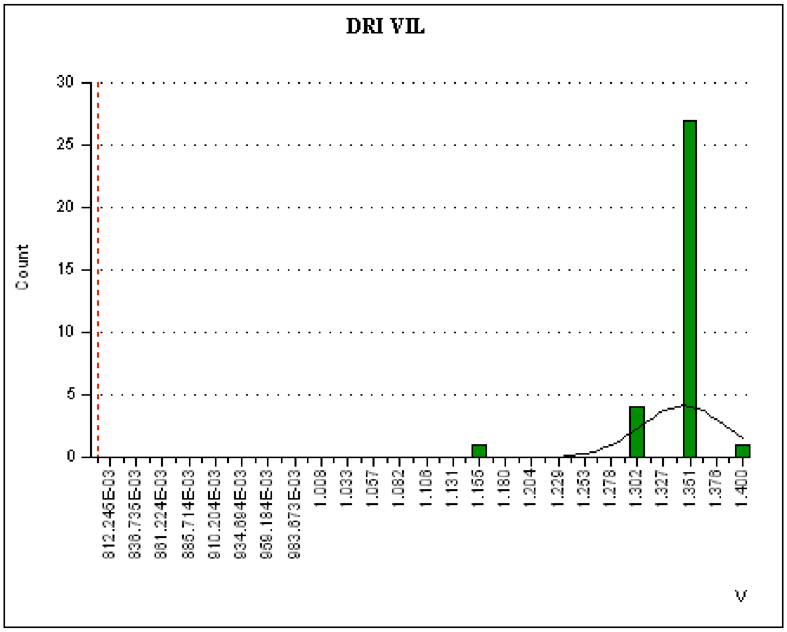
Min	1.300	**Skew**	N/A
Max	1.300	**StatHigh**	N/A
Mean	1.300	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.300	**90%**	1.300
		Range	0
Mean-3*StdDev	1.300	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.003, Test.Name=DRI VIL



Statistics: (V)

Min	1.150	**StatLow**	N/A
Max	1.400	**NWithinSpec**	33
Mean	1.339	**NOutsideSpec**	0
StdDev	39.047E-03	**90%**	1.350
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.457	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.222	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-3.7905		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

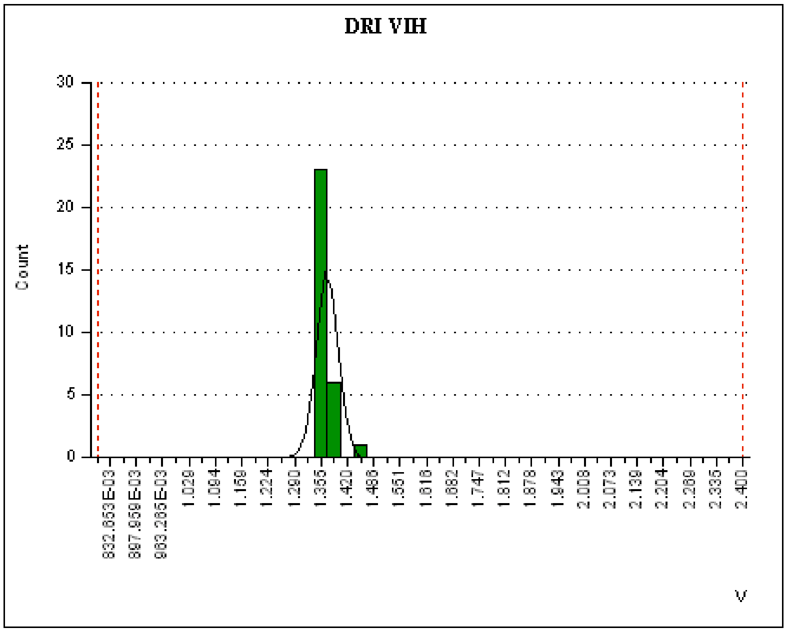
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=20.004, Test.Name=DRI VIH



Statistics: (V)

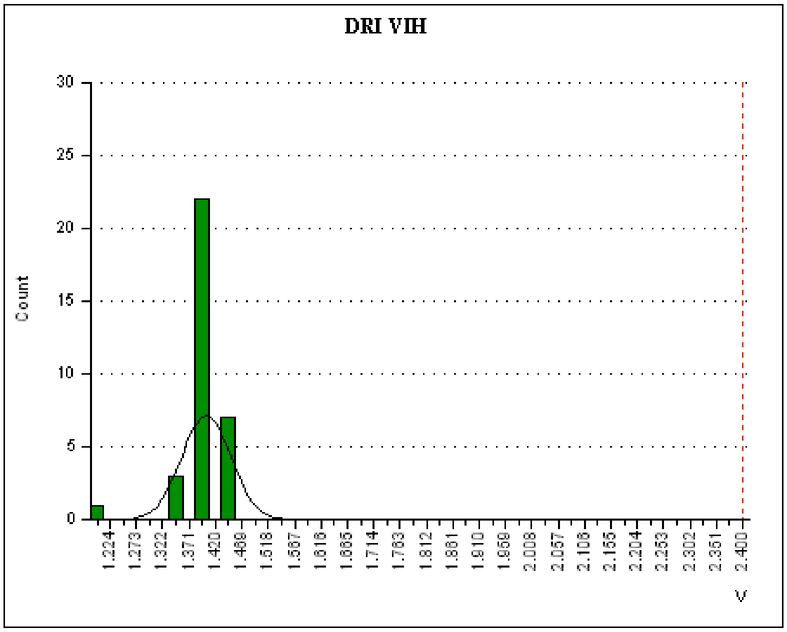
Min	1.350	**Skew**	1.8666
Max	1.450	**StatHigh**	N/A
Mean	1.363	**StatLow**	N/A
StdDev	26.041E-03	**NWithinSpec**	30
25%	1.350	**NOutsideSpec**	0
Mean+3*StdDev	1.441	**90%**	1.400
		Range	99.999E-03
Mean-3*StdDev	1.285	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.004, Test.Name=DRI VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.450	**NWithinSpec**	33
Mean	1.400	**NOutsideSpec**	0
StdDev	45.069E-03	**90%**	1.450
25%	1.400	**Range**	250.000E-03
Mean+3*StdDev	1.535	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.265	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-2.7253		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

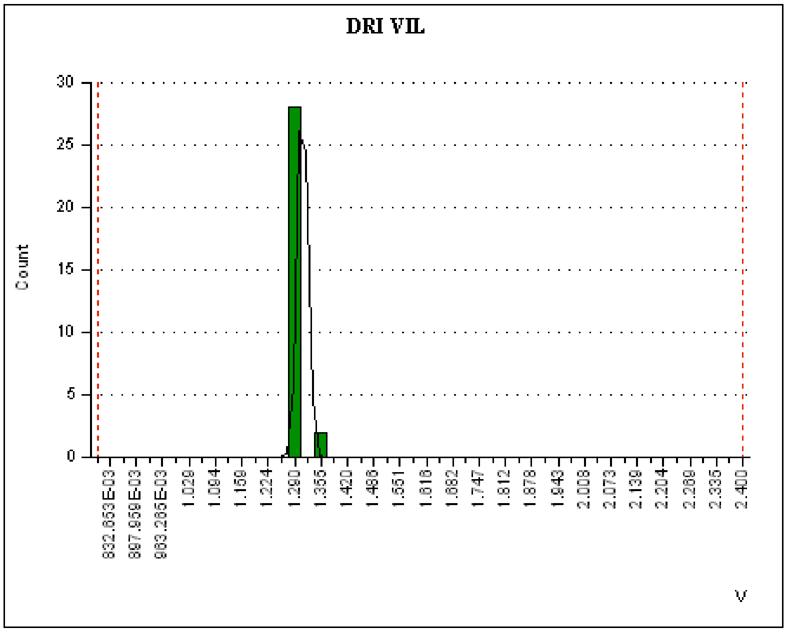
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=20.005, Test.Name=DRI VIL



Statistics: (V)

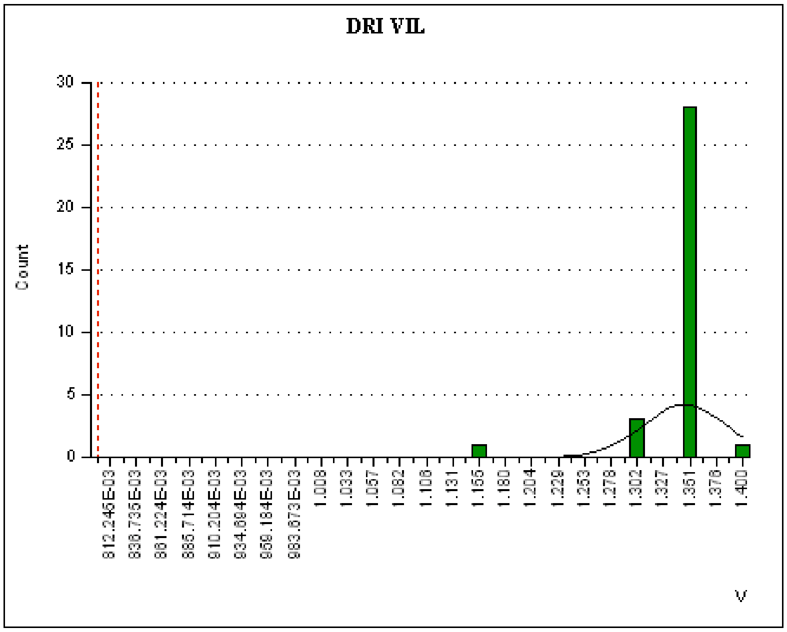
Min	1.300	**Skew**	3.6600
Max	1.350	**StatHigh**	N/A
Mean	1.303	**StatLow**	N/A
StdDev	12.685E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.341	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.265	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.005, Test.Name=DRI VIL



Statistics: (V)

Min	1.150	**StatLow**	N/A
Max	1.400	**NWithinSpec**	33
Mean	1.341	**NOutsideSpec**	0
StdDev	38.435E-03	**90%**	1.350
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.456	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.226	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-4.0637		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

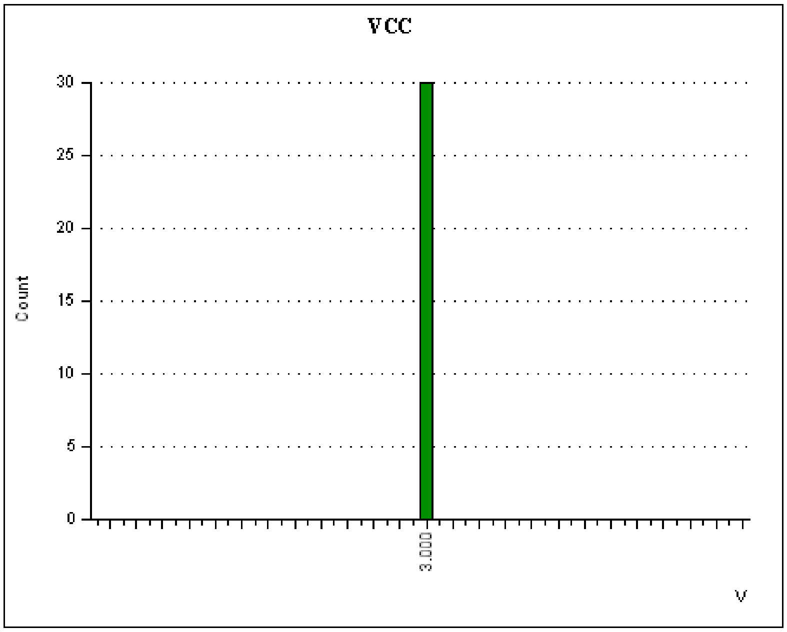
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=21.000, Test.Name=VCC



Statistics: (V)

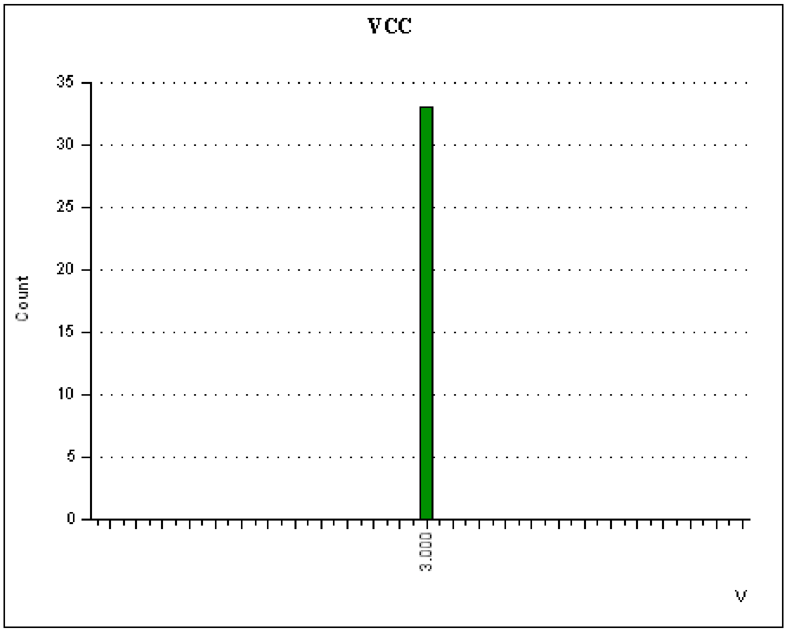
Min	3.000	**Skew**	N/A
Max	3.000	**StatHigh**	N/A
Mean	3.000	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	3.000	**NOutsideSpec**	N/A
Mean+3*StdDev	3.000	**90%**	3.000
		Range	0
Mean-3*StdDev	3.000	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=21.000, Test.Name=VCC



Statistics: (V)

Min	3.000	**StatLow**	N/A
Max	3.000	**NWithinSpec**	N/A
Mean	3.000	**NOutsideSpec**	N/A
StdDev	0	**90%**	3.000
25%	3.000	**Range**	0
Mean+3*StdDev	3.000	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	3.000	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	N/A		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

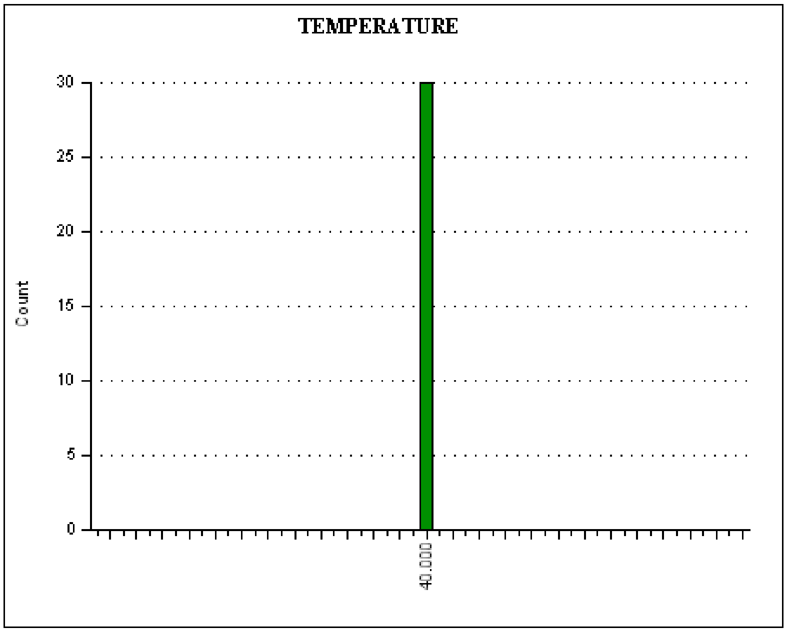
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=21.001, Test.Name=TEMPERATURE



Statistics

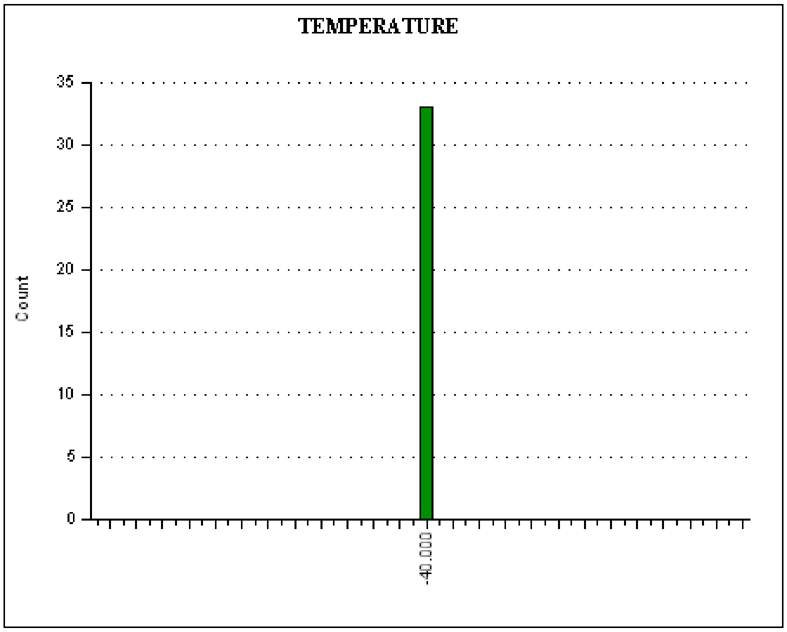
Min	40.000	**Skew**	N/A
Max	40.000	**StatHigh**	N/A
Mean	40.000	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	40.000	**NOutsideSpec**	N/A
Mean+3*StdDev	40.000	**90%**	40.000
		Range	0
Mean-3*StdDev	40.000	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oChar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=21.001, Test.Name=TEMPERATURE



Statistics

Min	-40.000	**StatLow**	N/A
Max	-40.000	**NWithinSpec**	N/A
Mean	-40.000	**NOutsideSpec**	N/A
StdDev	0	**90%**	-40.000
25%	-40.000	**Range**	0
Mean+3*StdDev	-40.000	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-40.000	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	N/A		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

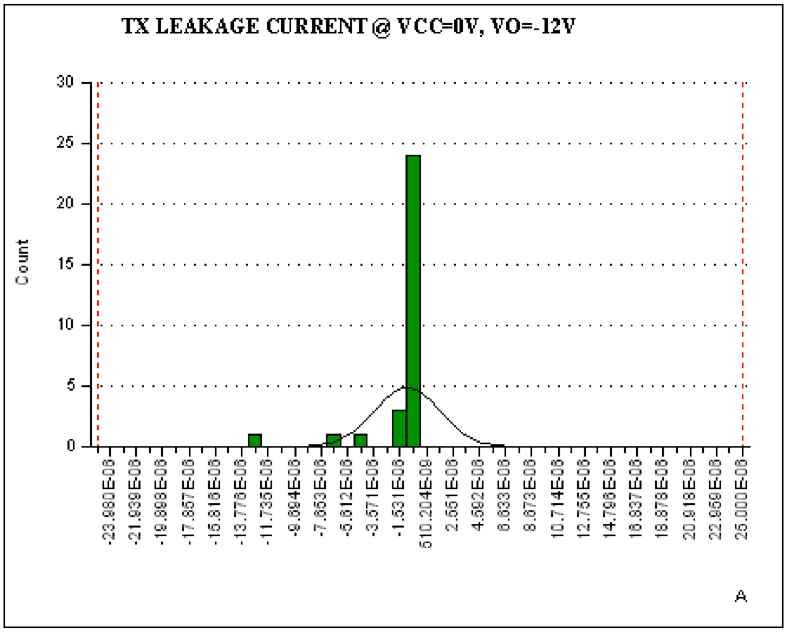
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=22.000, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

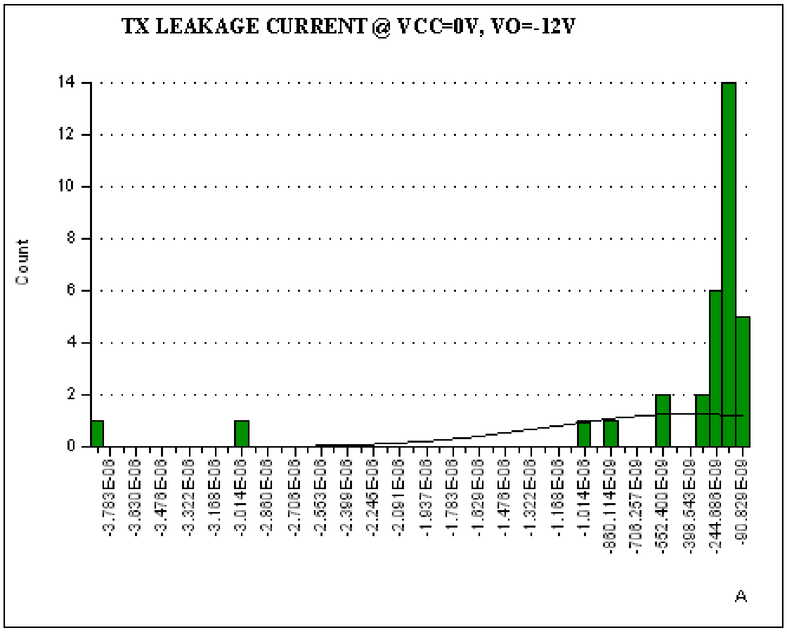
Min	-12.368E-06	**Skew**	-3.6327
Max	-83.739E-09	**StatHigh**	N/A
Mean	-1.246E-06	**StatLow**	N/A
StdDev	2.514E-06	**NWithinSpec**	30
25%	-901.044E-09	**NOutsideSpec**	0
Mean+3*StdDev	6.296E-06	**90%**	-119.973E-09
		Range	12.285E-06
Mean-3*StdDev	-8.788E-06	**NOutsideSpec**	0
Cpk	3.1497		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.000, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-3.860E-06	**StatLow**	N/A
Max	-90.829E-09	**NWithinSpec**	N/A
Mean	-445.779E-09	**NOutsideSpec**	N/A
StdDev	802.150E-09	**90%**	-111.330E-09
25%	-266.021E-09	**Range**	3.769E-06
Mean+3*StdDev	1.961E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-2.852E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-3.6044		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

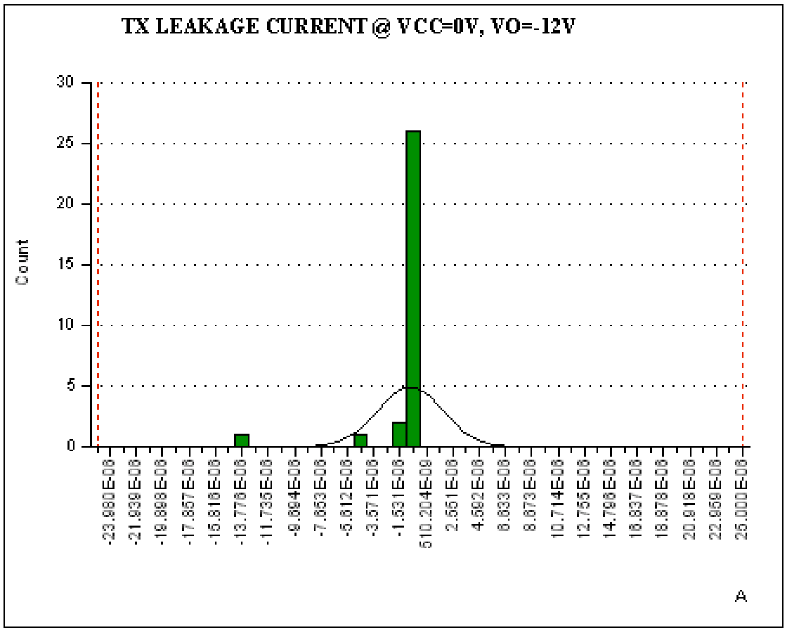
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=22.001, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

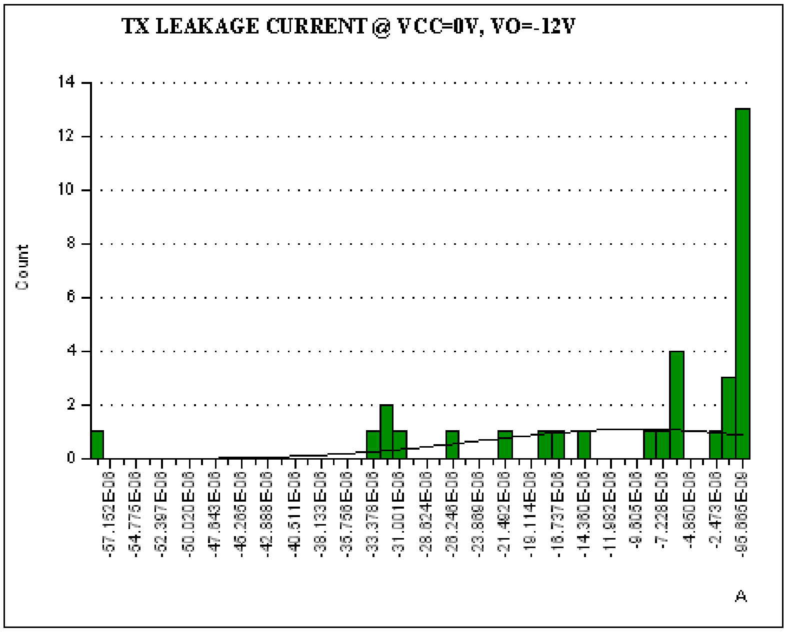
Min	-13.554E-06	**Skew**	-4.8266
Max	-72.393E-09	**StatHigh**	N/A
Mean	-997.503E-09	**StatLow**	N/A
StdDev	2.485E-06	**NWithinSpec**	30
25%	-599.379E-09	**NOutsideSpec**	0
Mean+3*StdDev	6.456E-06	**90%**	-121.667E-09
		Range	13.482E-06
Mean-3*StdDev	-8.451E-06	**NOutsideSpec**	0
Cpk	3.2203		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.001, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-58.341E-06	**StatLow**	N/A
Max	-95.665E-09	**NWithinSpec**	N/A
Mean	-10.065E-06	**NOutsideSpec**	N/A
StdDev	14.179E-06	**90%**	-131.977E-09
25%	-16.226E-06	**Range**	58.245E-06
Mean+3*StdDev	32.472E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-52.602E-06	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-1.7091		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

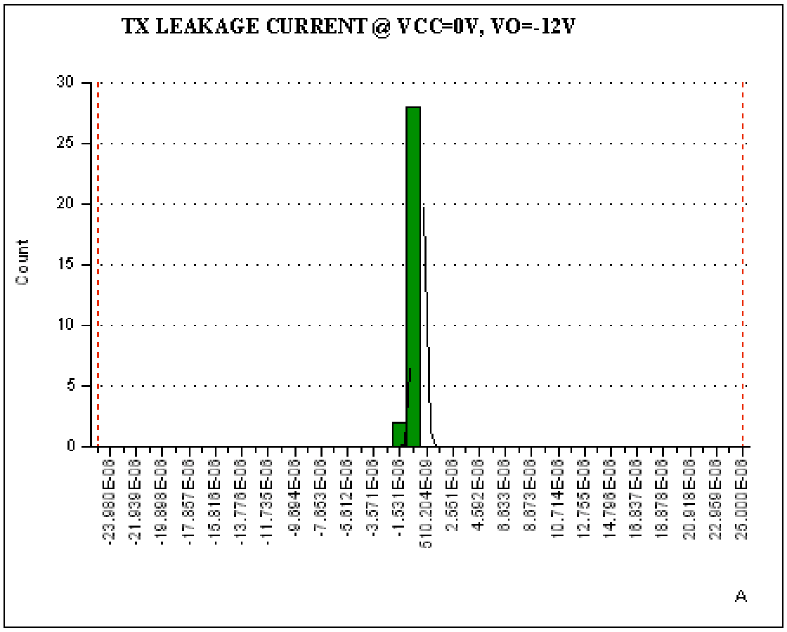
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=22.002, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

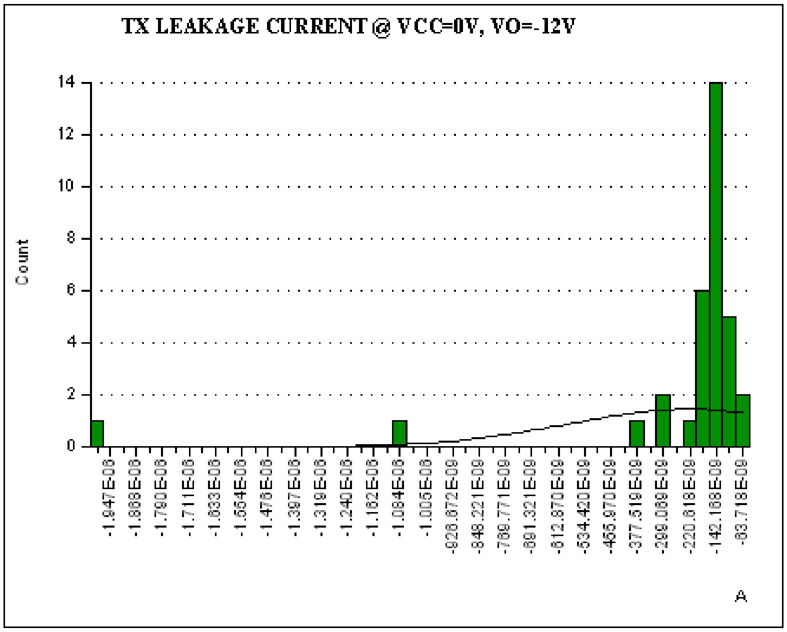
Min	-1.502E-06	**Skew**	-2.1112
Max	-103.911E-09	**StatHigh**	N/A
Mean	-371.625E-09	**StatLow**	N/A
StdDev	339.622E-09	**NWithinSpec**	30
25%	-347.365E-09	**NOutsideSpec**	0
Mean+3*StdDev	647.240E-09	**90%**	-111.500E-09
		Range	1.398E-06
Mean-3*StdDev	-1.390E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.002, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-1.986E-06	**StatLow**	N/A
Max	-63.718E-09	**NWithinSpec**	N/A
Mean	-240.903E-09	**NOutsideSpec**	N/A
StdDev	357.316E-09	**90%**	-108.399E-09
25%	-170.226E-09	**Range**	1.922E-06
Mean+3*StdDev	831.045E-09	**NOutsideSpec**	N/A
Mean-3*StdDev	-1.313E-06	**Cp**	N/A
Cpk	N/A	**Cpl**	N/A
Skew	-4.2671	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

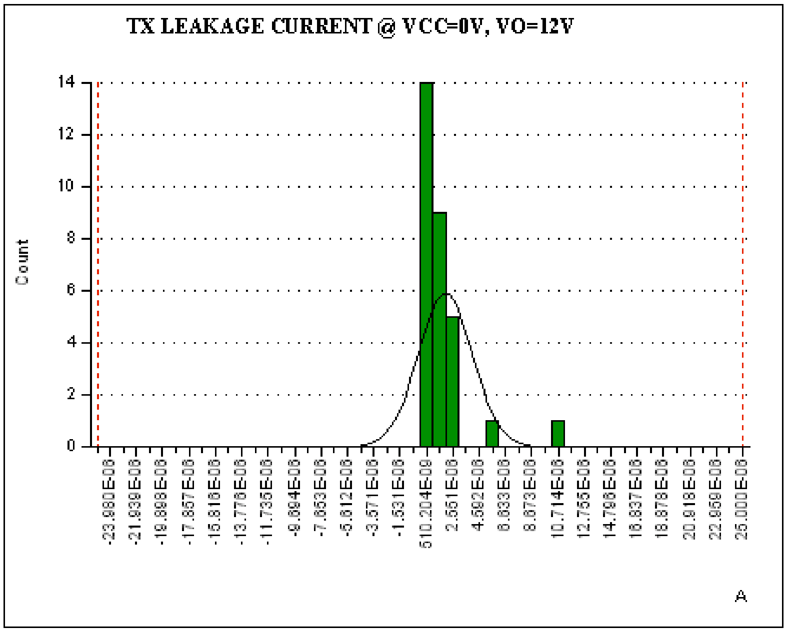
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=22.003, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

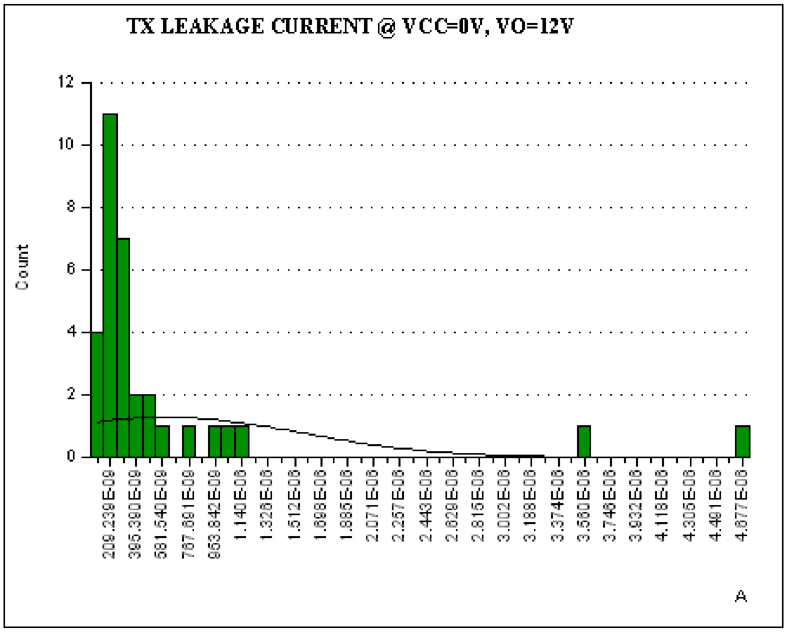
Min	166.801E-09	**Skew**	3.7073
Max	11.164E-06	**StatHigh**	N/A
Mean	1.664E-06	**StatLow**	N/A
StdDev	2.065E-06	**NWithinSpec**	30
25%	698.392E-09	**NOutsideSpec**	0
Mean+3*StdDev	7.860E-06	**90%**	2.746E-06
		Range	10.997E-06
Mean-3*StdDev	-4.532E-06	**NOutsideSpec**	0
Cpk	3.7665		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.003, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	116.163E-09	**StatLow**	N/A
Max	4.677E-06	**NWithinSpec**	N/A
Mean	590.750E-09	**NOutsideSpec**	N/A
StdDev	951.220E-09	**90%**	1.082E-06
25%	208.229E-09	**Range**	4.561E-06
Mean+3*StdDev	3.444E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-2.263E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.5729		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

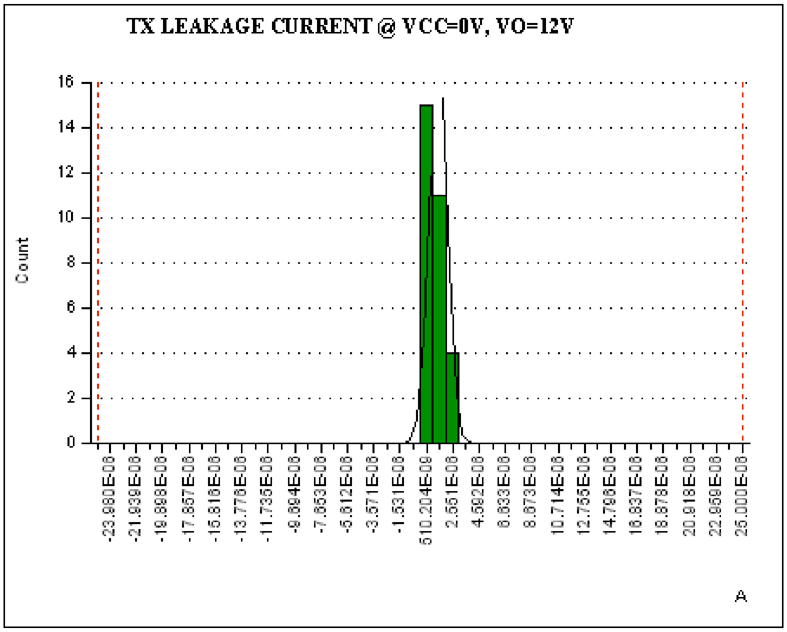
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=22.004, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

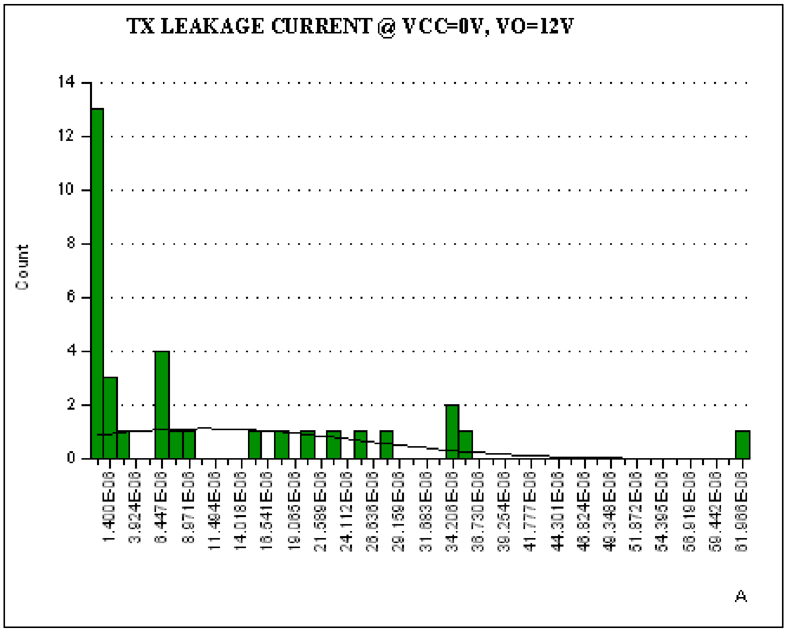
Min	128.651E-09	**Skew**	0.7150
Max	2.862E-06	**StatHigh**	N/A
Mean	1.119E-06	**StatLow**	N/A
StdDev	684.851E-09	**NWithinSpec**	30
25%	580.399E-09	**NOutsideSpec**	0
Mean+3*StdDev	3.174E-06	**90%**	2.099E-06
		Range	2.733E-06
Mean-3*StdDev	-935.108E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.004, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	138.130E-09	**StatLow**	N/A
Max	61.966E-06	**NWithinSpec**	N/A
Mean	10.463E-06	**NOutsideSpec**	N/A
StdDev	14.703E-06	**90%**	33.605E-06
25%	383.209E-09	**Range**	61.828E-06
Mean+3*StdDev	54.573E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-33.648E-06	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.7972		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

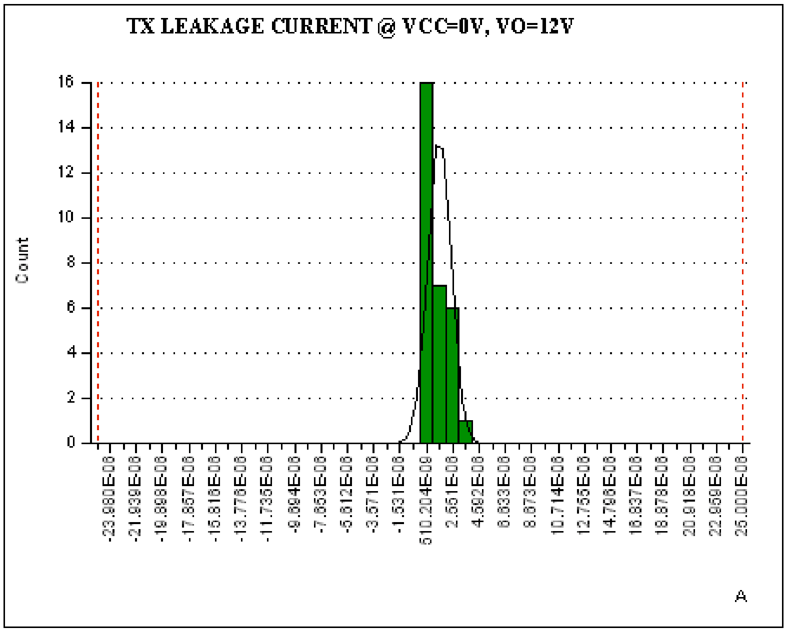
Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Thu 30 Mar 2006, 12:27 PM

Test.Number=22.005, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

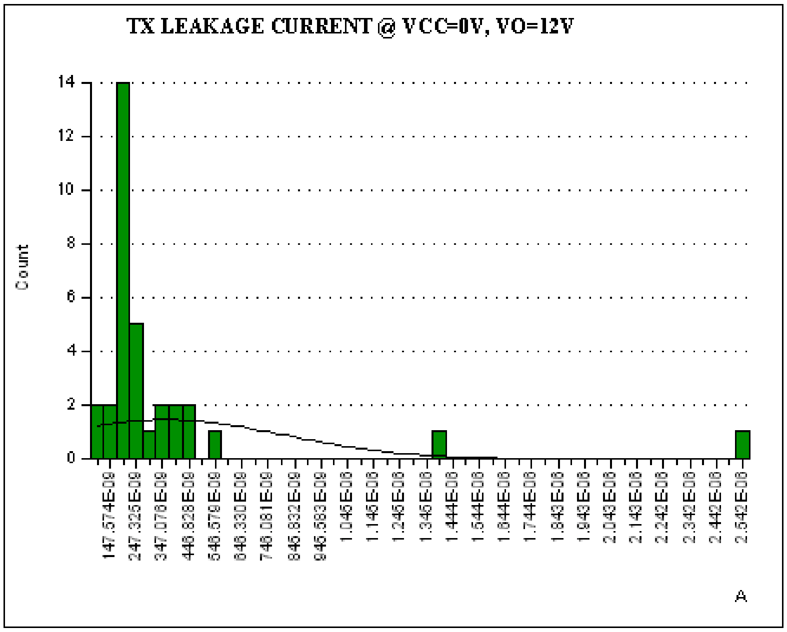
Min	173.579E-09	**Skew**	1.1386
Max	3.740E-06	**StatHigh**	N/A
Mean	1.227E-06	**StatLow**	N/A
StdDev	892.939E-09	**NWithinSpec**	30
25%	549.618E-09	**NOutsideSpec**	0
Mean+3*StdDev	3.906E-06	**90%**	2.510E-06
		Range	3.567E-06
Mean-3*StdDev	-1.452E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3V_40oCchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.005, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	97.699E-09	**StatLow**	N/A
Max	2.542E-06	**NWithinSpec**	N/A
Mean	350.943E-09	**NOutsideSpec**	N/A
StdDev	450.465E-09	**90%**	428.102E-09
25%	196.879E-09	**Range**	2.444E-06
Mean+3*StdDev	1.702E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-1.000E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	4.1884		
StatHigh	N/A		

Attributes

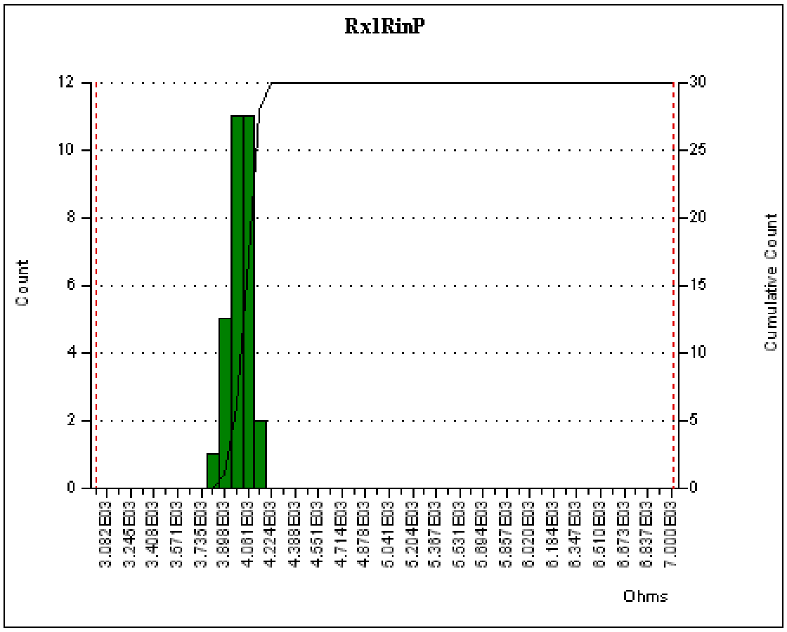
Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cc3: N/A	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	11-JUL-2003	N/A	SP3243ECH.AT	3	0

Conditions

Vcc	temp
3V	-40C

Data: Raw Data

Test.Number=28.0, Test.Name=Rx1RinP



Statistics: (Ohms)

Max	4.126E03	**25%**	3.954E03	**SpecHigh**	7.000E03
Mean	3.997E03	**10%**	3.892E03	**SpecLow**	3.000E03
Min	3.823E03	**N**	30	**PctWithinSpec**	100.00
Range	303.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	69.480	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9523	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1951	**Cpk**	>4.0000		
90%	4.067E03	**Skew**	-0.6291		
75%	4.035E03	**Kurtosis**	0.2690		
Median	4.019E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

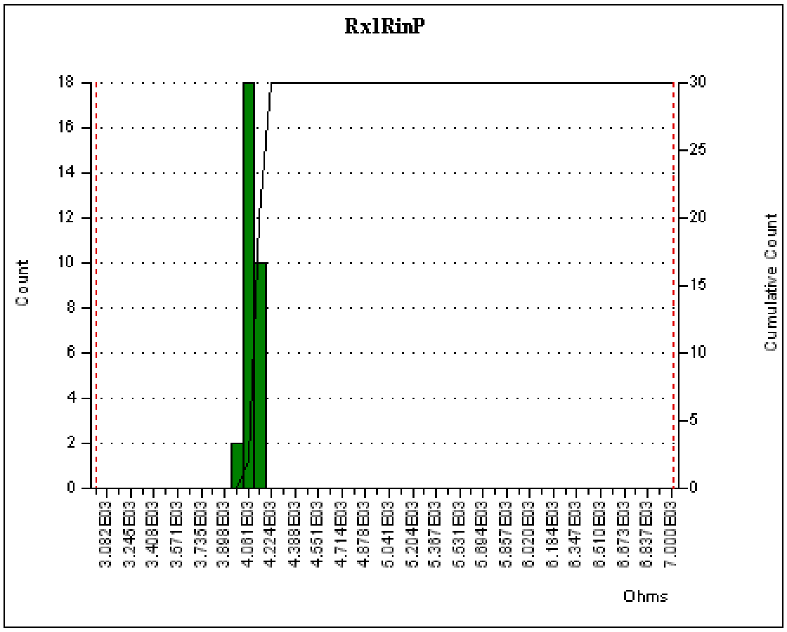
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=28.0, Test.Name=Rx1RinP



Statistics: (Ohms)

Max	4.157E03	**25%**	4.065E03	**SpecHigh**	7.000E03
Mean	4.088E03	**10%**	4.029E03	**SpecLow**	3.000E03
Min	3.979E03	**N**	30	**PctWithinSpec**	100.00
Range	178.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	43.922	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9553	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2344	**Cpk**	>4.0000		
90%	4.141E03	**Skew**	-0.4931		
75%	4.132E03	**Kurtosis**	0.1068		
Median	4.084E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

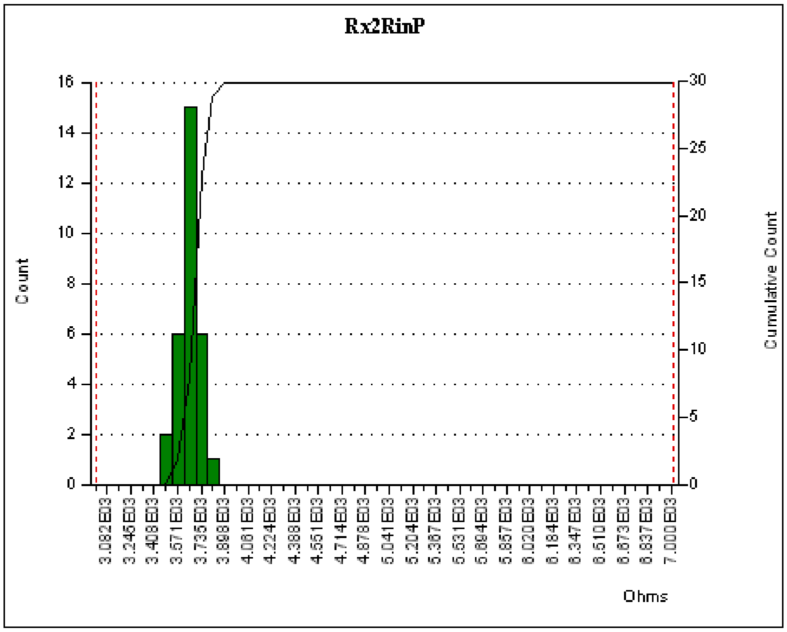
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=29.0, Test.Name=Rx2RinP



Statistics: (Ohms)

Max	3.777E03	**25%**	3.605E03	**SpecHigh**	7.000E03
Mean	3.648E03	**10%**	3.546E03	**SpecLow**	3.000E03
Min	3.487E03	**N**	30	**PctWithinSpec**	100.00
Range	290.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	66.699	**Cpl**	3.2394	**NWithinSpec**	30
W	0.9575	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2678	**Cpk**	3.2394		
90%	3.711E03	**Skew**	-0.5411		
75%	3.688E03	**Kurtosis**	0.2154		
Median	3.666E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

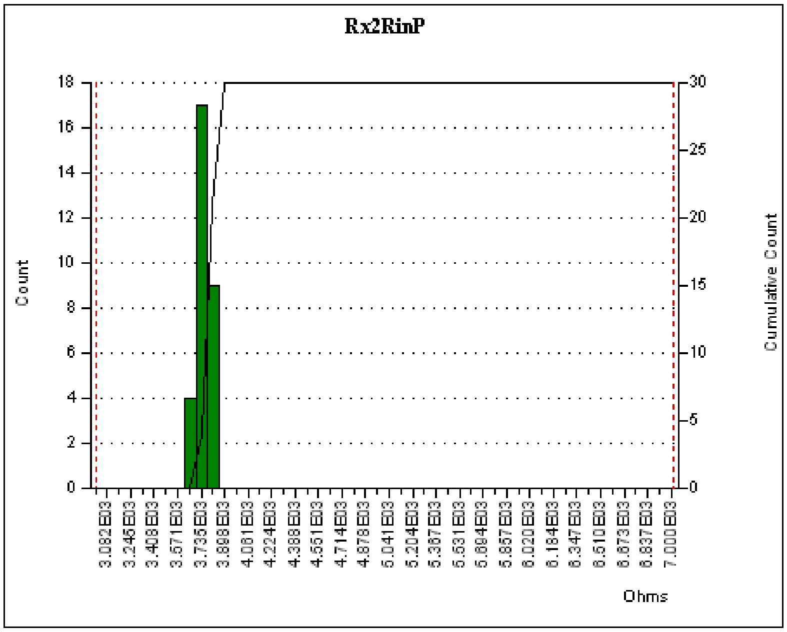
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=29.0, Test.Name=Rx2RinP



Statistics: (Ohms)

Max	3.816E03	**25%**	3.713E03	**SpecHigh**	7.000E03
Mean	3.737E03	**10%**	3.677E03	**SpecLow**	3.000E03
Min	3.613E03	**N**	30	**PctWithinSpec**	100.00
Range	203.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	49.374	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9547	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2260	**Cpk**	>4.0000		
90%	3.800E03	**Skew**	-0.5221		
75%	3.783E03	**Kurtosis**	0.3540		
Median	3.732E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

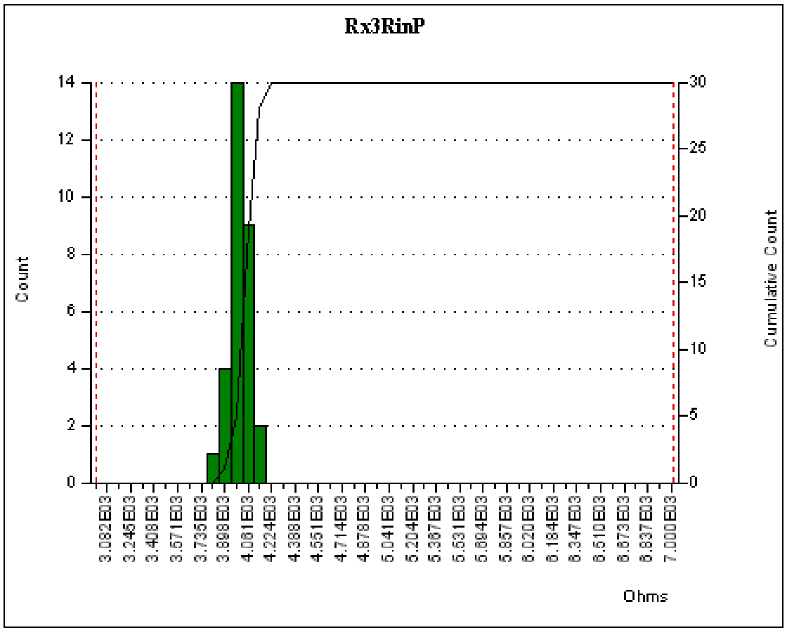
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=30.0, Test.Name=Rx3RinP



Statistics: (Ohms)

Max	4.128E03	**25%**	3.959E03	**SpecHigh**	7.000E03
Mean	3.996E03	**10%**	3.894E03	**SpecLow**	3.000E03
Min	3.828E03	**N**	30	**PctWithinSpec**	100.00
Range	300.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	67.220	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9608	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.3242	**Cpk**	>4.0000		
90%	4.061E03	**Skew**	-0.5566		
75%	4.030E03	**Kurtosis**	0.3537		
Median	4.018E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

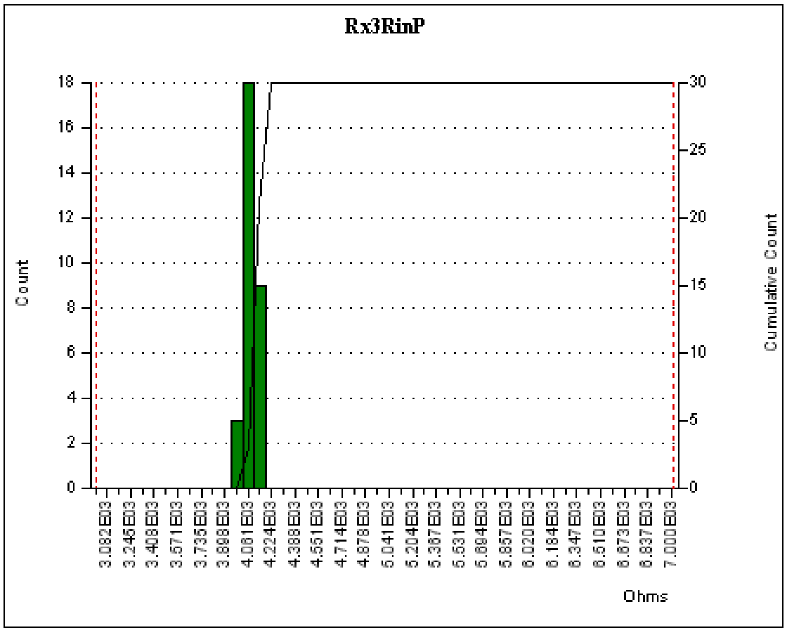
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=30.0, Test.Name=Rx3RinP



Statistics: (Ohms)

Max	4.178E03	**25%**	4.064E03	**SpecHigh**	7.000E03
Mean	4.086E03	**10%**	4.018E03	**SpecLow**	3.000E03
Min	3.971E03	**N**	30	**PctWithinSpec**	100.00
Range	207.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	48.708	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9635	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.3793	**Cpk**	>4.0000		
90%	4.147E03	**Skew**	-0.4539		
75%	4.129E03	**Kurtosis**	0.2589		
Median	4.091E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

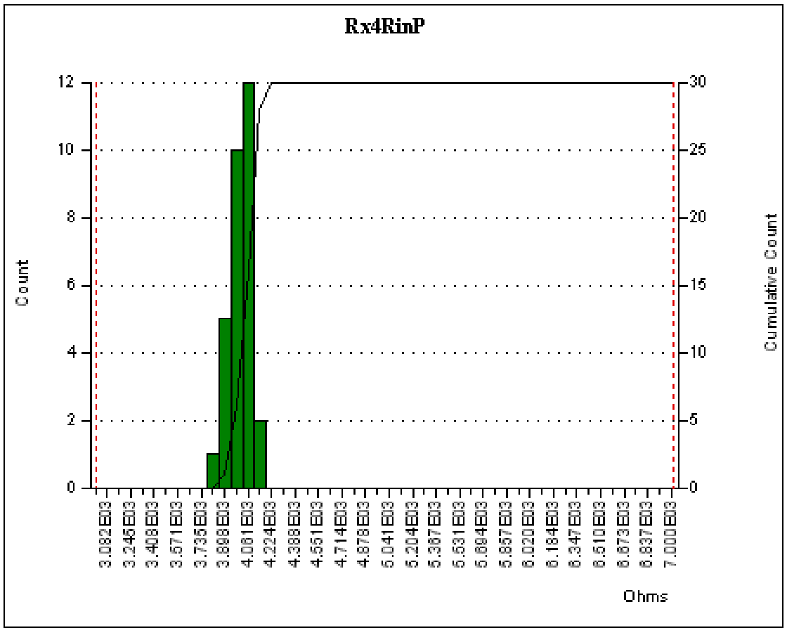
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=31.0, Test.Name=Rx4RinP



Statistics: (Ohms)

Max	4.138E03	**25%**	3.951E03	**SpecHigh**	7.000E03
Mean	3.997E03	**10%**	3.893E03	**SpecLow**	3.000E03
Min	3.838E03	**N**	30	**PctWithinSpec**	100.00
Range	300.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	67.817	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9598	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.3065	**Cpk**	>4.0000		
90%	4.062E03	**Skew**	-0.4338		
75%	4.038E03	**Kurtosis**	0.2259		
Median	4.016E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

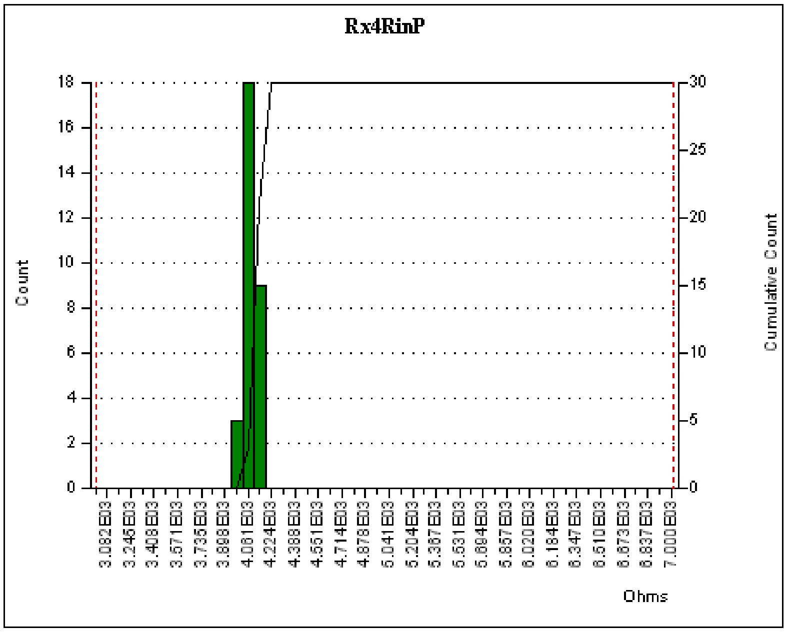
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=31.0, Test.Name=Rx4RinP



Statistics: (Ohms)

Max	4.166E03	**25%**	4.058E03	**SpecHigh**	7.000E03
Mean	4.083E03	**10%**	4.024E03	**SpecLow**	3.000E03
Min	3.954E03	**N**	30	**PctWithinSpec**	100.00
Range	212.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	49.702	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9616	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.3396	**Cpk**	>4.0000		
90%	4.148E03	**Skew**	-0.4811		
75%	4.125E03	**Kurtosis**	0.4637		
Median	4.081E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

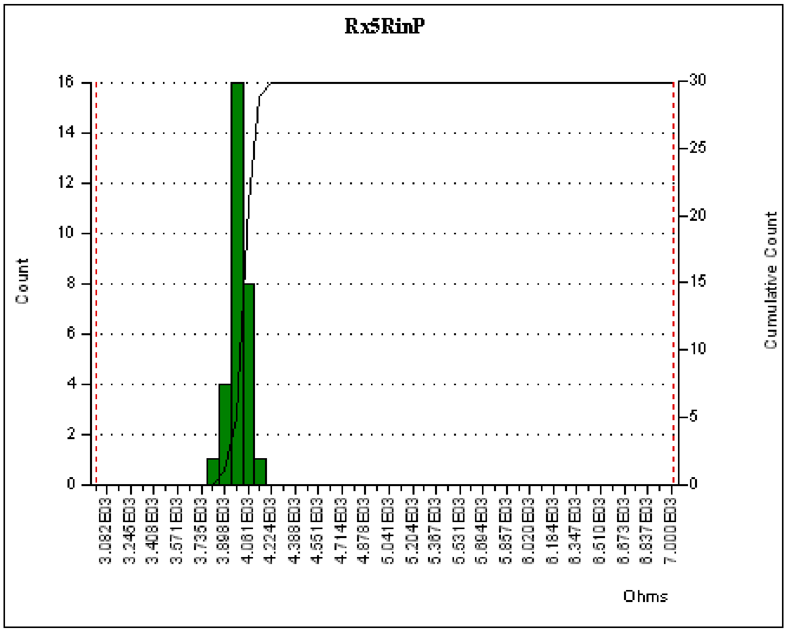
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=32.0, Test.Name=Rx5RinP



Statistics: (Ohms)

Max	4.127E03	**25%**	3.955E03	**SpecHigh**	7.000E03
Mean	3.991E03	**10%**	3.889E03	**SpecLow**	3.000E03
Min	3.833E03	**N**	30	**PctWithinSpec**	100.00
Range	294.000	**Cp**	>4.0000		
StdDev	66.140	**Cpl**	>4.0000	**PctDefSpec**	0
W	0.9579	**Cpu**	>4.0000	**NWithinSpec**	30
WpValue	0.2742	**Cpk**	>4.0000	**NOutsideSpec**	0
90%	4.058E03	**Skew**	-0.5236		
75%	4.026E03	**Kurtosis**	0.3719		
Median	4.007E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

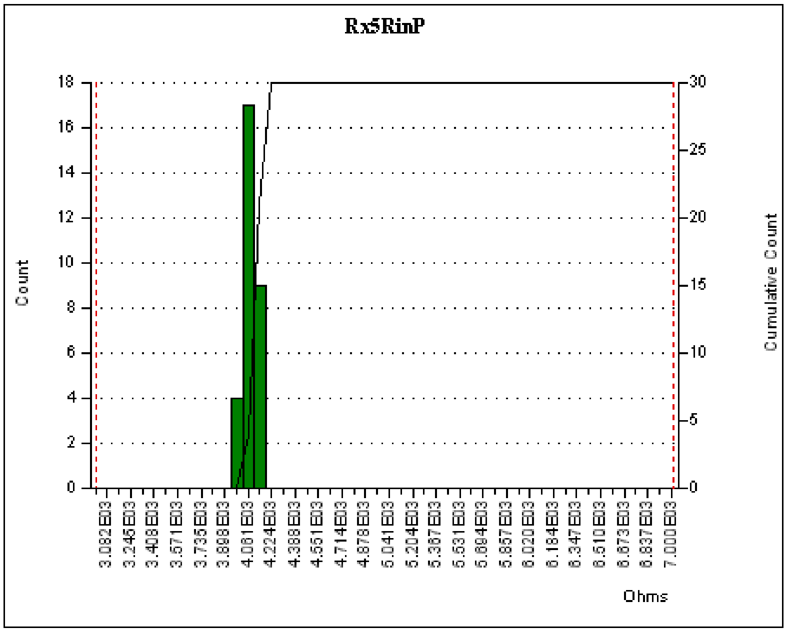
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=32.0, Test.Name=Rx5RinP



Statistics: (Ohms)

Max	4.163E03	**25%**	4.062E03	**SpecHigh**	7.000E03
Mean	4.081E03	**10%**	4.011E03	**SpecLow**	3.000E03
Min	3.957E03	**N**	30	**PctWithinSpec**	100.00
Range	206.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	50.945	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9617	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.3430	**Cpk**	>4.0000		
90%	4.149E03	**Skew**	-0.4333		
75%	4.125E03	**Kurtosis**	0.0707		
Median	4.079E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

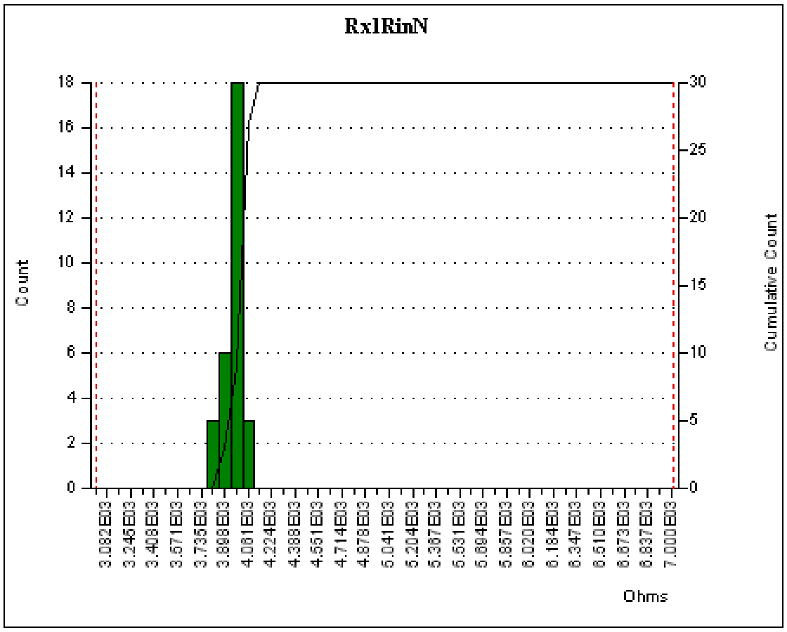
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=33.0, Test.Name=Rx1RinN



Statistics: (Ohms)

Max	4.086E03	**25%**	3.916E03	**SpecHigh**	7.000E03
Mean	3.959E03	**10%**	3.856E03	**SpecLow**	3.000E03
Min	3.787E03	**N**	30	**PctWithinSpec**	100.00
Range	299.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	68.386	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9522	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1937	**Cpk**	>4.0000		
90%	4.027E03	**Skew**	-0.6266		
75%	3.997E03	**Kurtosis**	0.2770		
Median	3.981E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

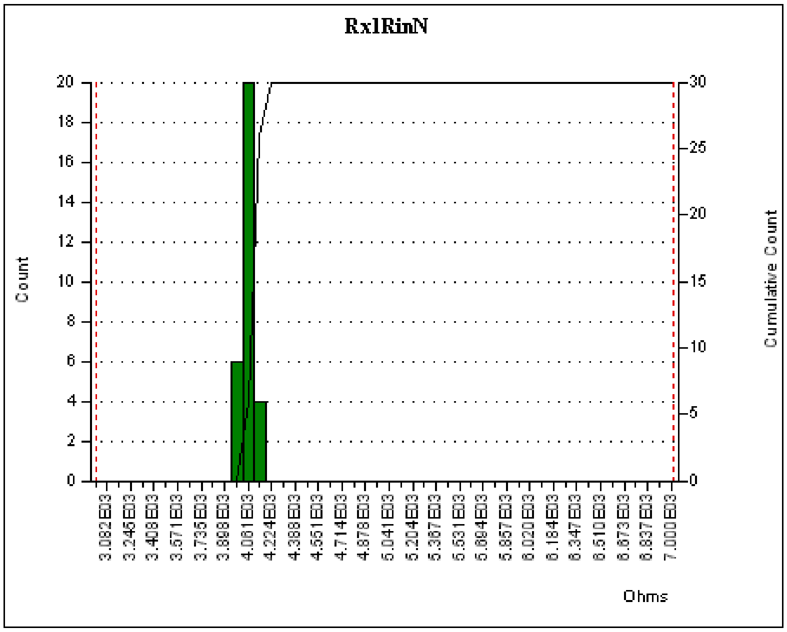
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=33.0, Test.Name=Rx1RinN



Statistics: (Ohms)

Max	4.121E03	**25%**	4.033E03	**SpecHigh**	7.000E03
Mean	4.054E03	**10%**	3.997E03	**SpecLow**	3.000E03
Min	3.947E03	**N**	30	**PctWithinSpec**	100.00
Range	174.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	43.076	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9525	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1970	**Cpk**	>4.0000		
90%	4.107E03	**Skew**	-0.4857		
75%	4.097E03	**Kurtosis**	0.0987		
Median	4.050E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

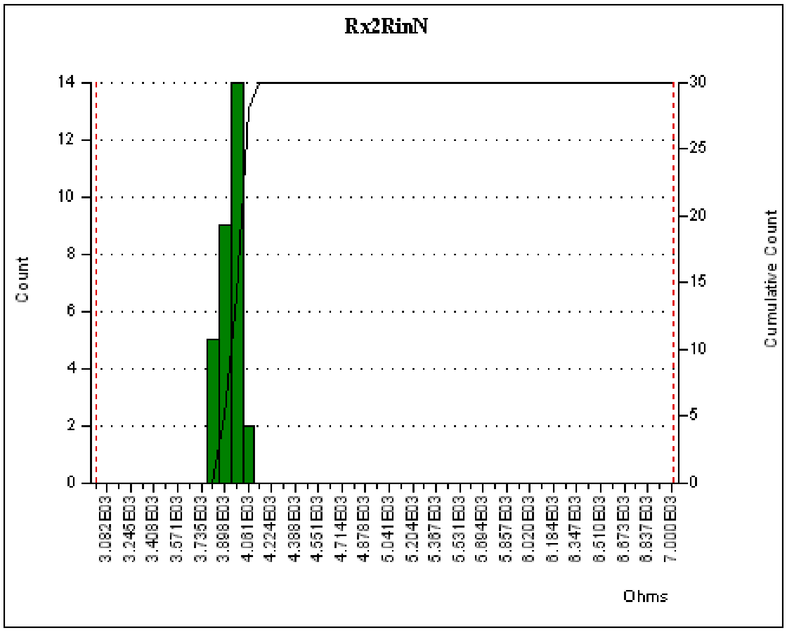
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=34.0, Test.Name=Rx2RinN



Statistics: (Ohms)

Max	4.052E03	**25%**	3.886E03	**SpecHigh**	7.000E03
Mean	3.929E03	**10%**	3.826E03	**SpecLow**	3.000E03
Min	3.780E03	**N**	30	**PctWithinSpec**	100.00
Range	272.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	64.921	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9474	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1442	**Cpk**	>4.0000		
90%	3.988E03	**Skew**	-0.5225		
75%	3.969E03	**Kurtosis**	0.0253		
Median	3.946E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

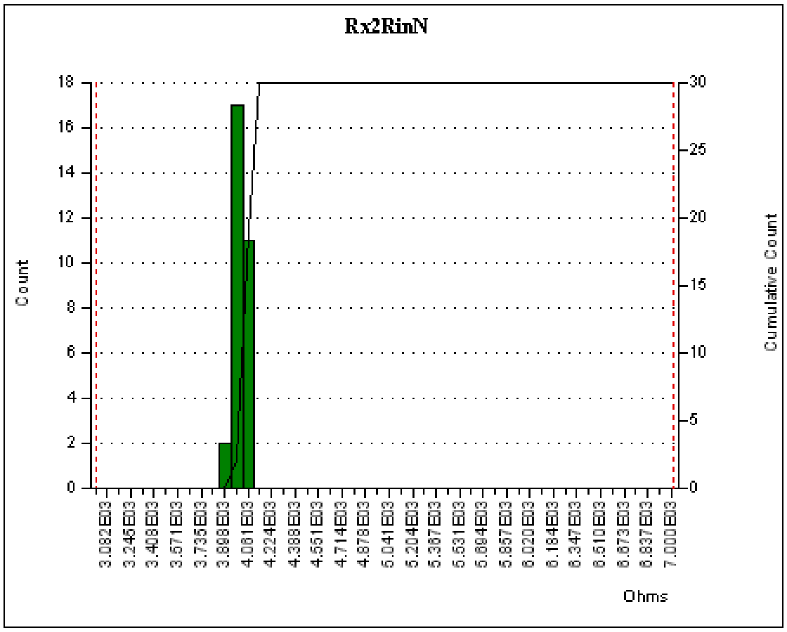
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=34.0, Test.Name=Rx2RinN



Statistics: (Ohms)

Max	4.099E03	**25%**	3.998E03	**SpecHigh**	7.000E03
Mean	4.020E03	**10%**	3.963E03	**SpecLow**	3.000E03
Min	3.899E03	**N**	30	**PctWithinSpec**	100.00
Range	200.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	48.160	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9436	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.1141	**Cpk**	>4.0000		
90%	4.083E03	**Skew**	-0.4721		
75%	4.065E03	**Kurtosis**	0.4314		
Median	4.017E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

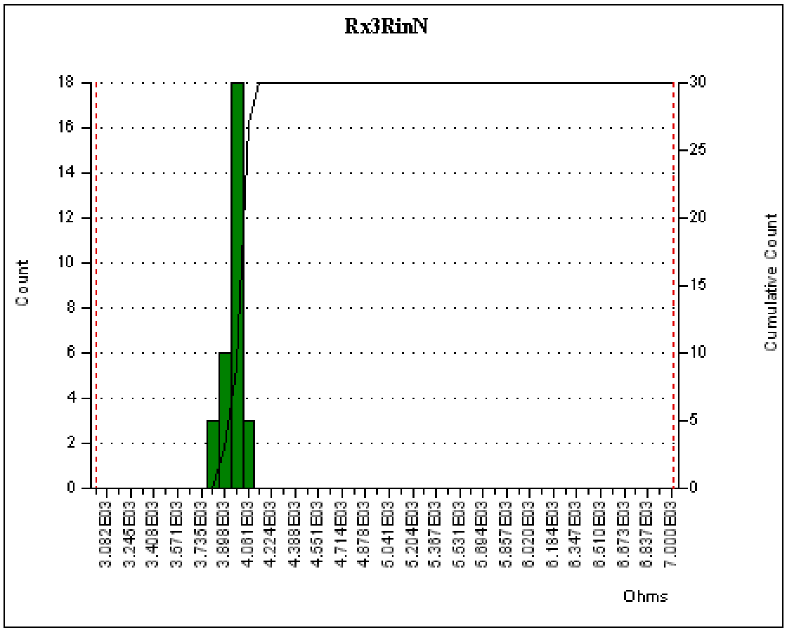
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=35.0, Test.Name=Rx3RinN



Statistics: (Ohms)

Max	4.089E03	**25%**	3.923E03	**SpecHigh**	7.000E03
Mean	3.959E03	**10%**	3.858E03	**SpecLow**	3.000E03
Min	3.793E03	**N**	30	**PctWithinSpec**	100.00
Range	296.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	66.486	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9600	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.3094	**Cpk**	>4.0000		
90%	4.023E03	**Skew**	-0.5576		
75%	3.994E03	**Kurtosis**	0.3579		
Median	3.979E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

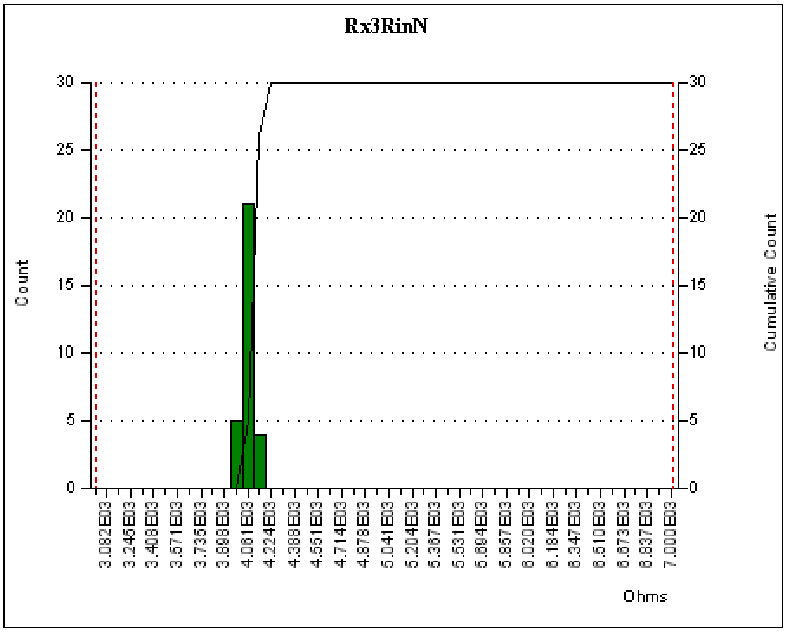
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=35.0, Test.Name=Rx3RinN



Statistics: (Ohms)

Max	4.143E03	**25%**	4.032E03	**SpecHigh**	7.000E03
Mean	4.054E03	**10%**	3.986E03	**SpecLow**	3.000E03
Min	3.940E03	**N**	30	**PctWithinSpec**	100.00
Range	203.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	48.021	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9607	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.3225	**Cpk**	>4.0000		
90%	4.114E03	**Skew**	-0.4552		
75%	4.096E03	**Kurtosis**	0.2672		
Median	4.058E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

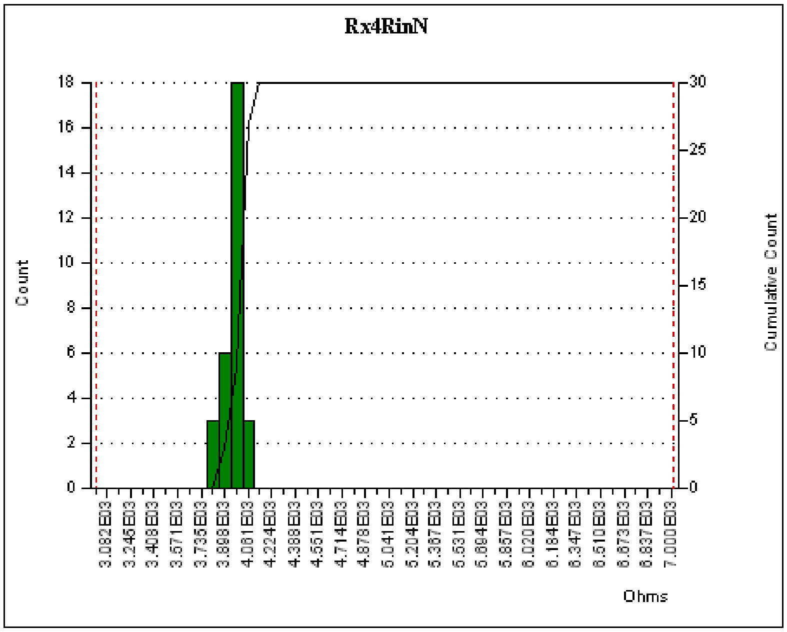
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=36.0, Test.Name=Rx4RinN



Statistics: (Ohms)

Max	4.099E03	**25%**	3.912E03	**SpecHigh**	7.000E03
Mean	3.960E03	**10%**	3.856E03	**SpecLow**	3.000E03
Min	3.801E03	**N**	30	**PctWithinSpec**	100.00
Range	298.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	67.184	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9594	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2986	**Cpk**	>4.0000		
90%	4.024E03	**Skew**	-0.4407		
75%	4.001E03	**Kurtosis**	0.2555		
Median	3.979E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

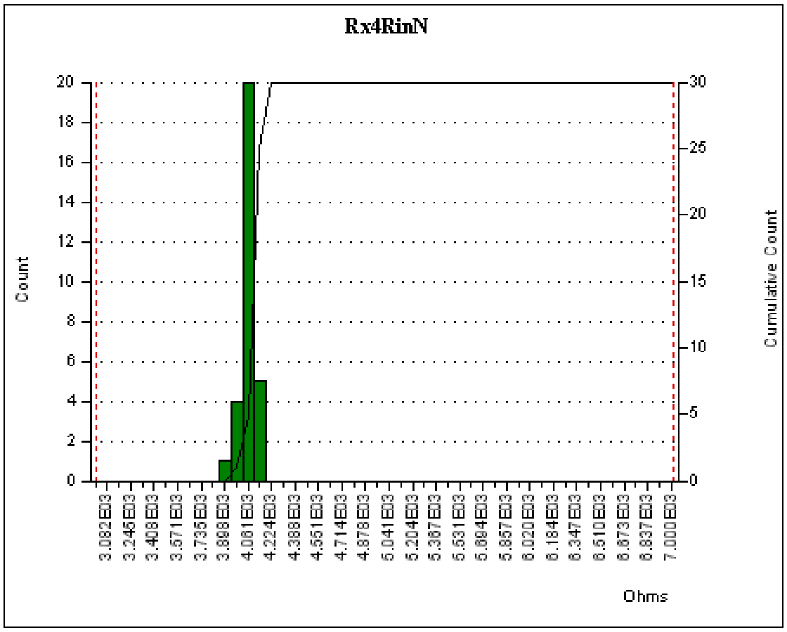
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=36.0, Test.Name=Rx4RinN



Statistics: (Ohms)

Max	4.129E03	**25%**	4.027E03	**SpecHigh**	7.000E03
Mean	4.050E03	**10%**	3.991E03	**SpecLow**	3.000E03
Min	3.923E03	**N**	30	**PctWithinSpec**	100.00
Range	206.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	49.038	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9556	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2383	**Cpk**	>4.0000		
90%	4.114E03	**Skew**	-0.4825		
75%	4.092E03	**Kurtosis**	0.4527		
Median	4.046E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

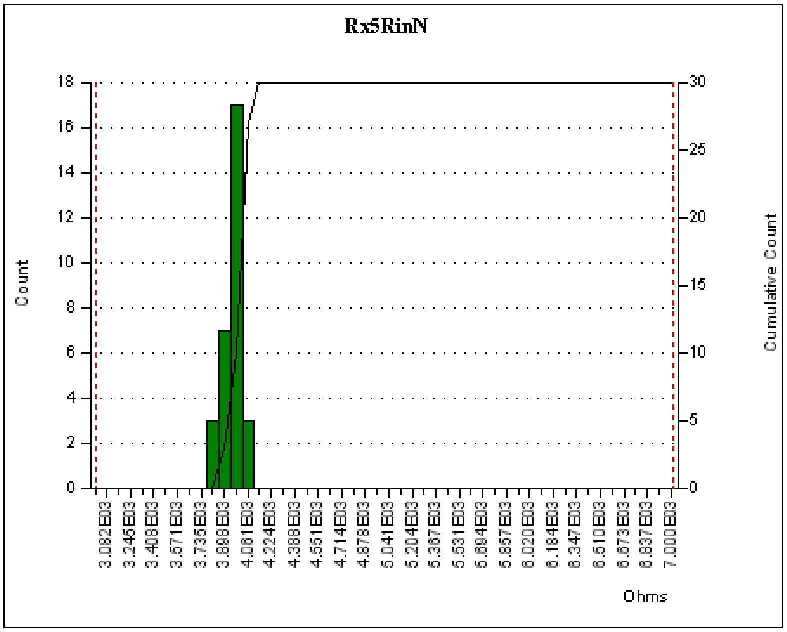
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=37.0, Test.Name=Rx5RinN



Statistics: (Ohms)

Max	4.088E03	**25%**	3.918E03	**SpecHigh**	7.000E03
Mean	3.953E03	**10%**	3.852E03	**SpecLow**	3.000E03
Min	3.797E03	**N**	30	**PctWithinSpec**	100.00
Range	291.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	65.418	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9574	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2660	**Cpk**	>4.0000		
90%	4.019E03	**Skew**	-0.5191		
75%	3.989E03	**Kurtosis**	0.3883		
Median	3.969E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Coldchar	Episil	2umcmos	23-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

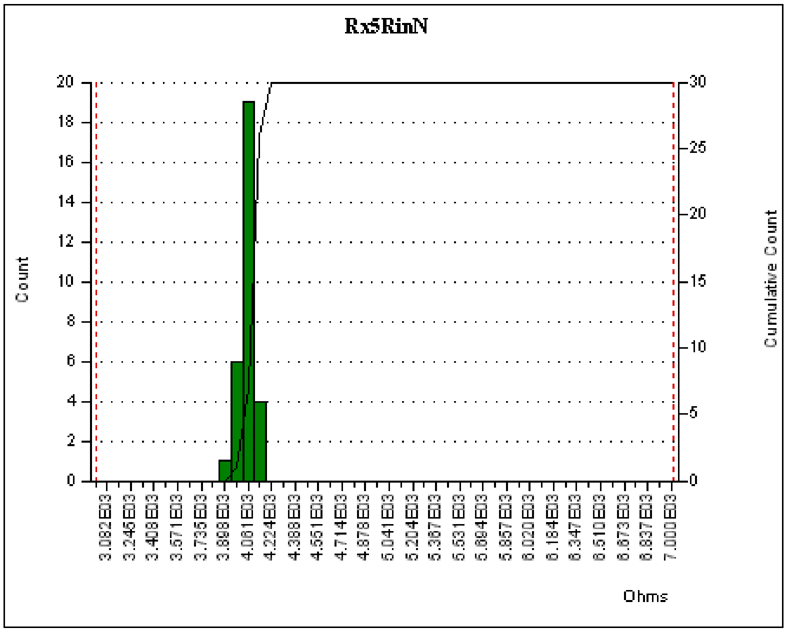
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=37.0, Test.Name=Rx5RinN



Statistics: (Ohms)

Max	4.125E03	**25%**	4.029E03	**SpecHigh**	7.000E03
Mean	4.047E03	**10%**	3.978E03	**SpecLow**	3.000E03
Min	3.925E03	**N**	30	**PctWithinSpec**	100.00
Range	200.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	50.369	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9562	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2469	**Cpk**	>4.0000		
90%	4.115E03	**Skew**	-0.4340		
75%	4.092E03	**Kurtosis**	0.0518		
Median	4.045E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
a130063chc: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	07-AUG-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

temp
-40C

Data: Raw Data

Stat limits applied

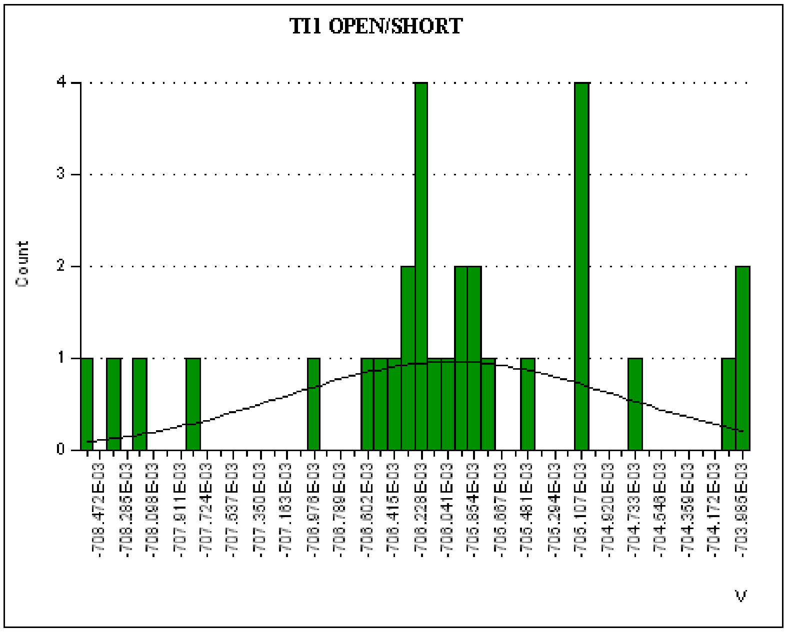
StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Thu 30 Mar 2006, 01:11 PM

Test.Number=1.000, Test.Name=TI1 OPEN/SHORT



Statistics: (V)

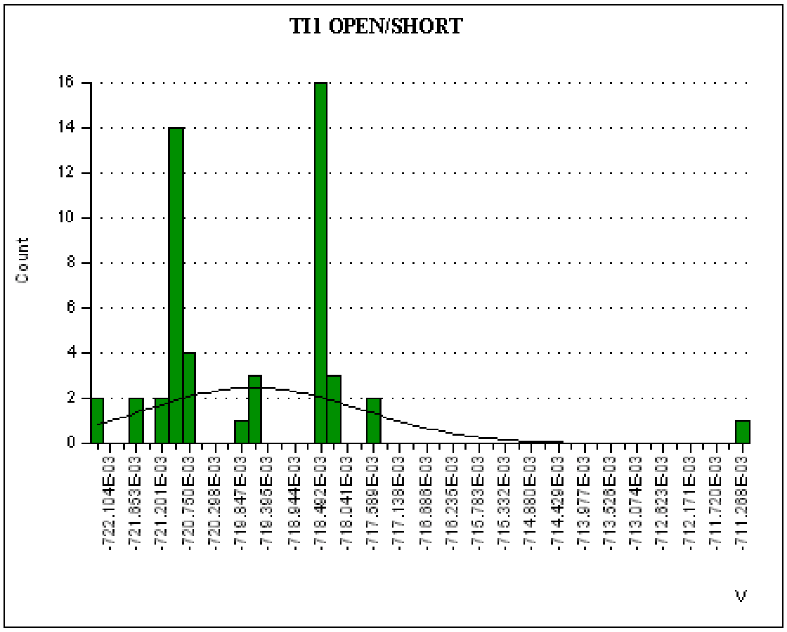
Min	-708.565E-03	**Skew**	-0.3402
Max	-703.985E-03	**StatHigh**	N/A
Mean	-706.038E-03	**StatLow**	N/A
StdDev	1.159E-03	**NWithinSpec**	N/A
25%	-706.428E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-702.561E-03	**90%**	-704.405E-03
		Range	4.580E-03
Mean-3*StdDev	-709.516E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=1.000, Test.Name=TI1 OPEN/SHORT



Statistics: (V)

Min	-722.330E-03	**StatLow**	N/A
Max	-711.268E-03	**NWithinSpec**	N/A
Mean	-719.666E-03	**NOutsideSpec**	N/A
StdDev	1.819E-03	**90%**	-718.277E-03
25%	-720.966E-03	**Range**	11.062E-03
Mean+3*StdDev	-714.209E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-725.123E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.9308		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

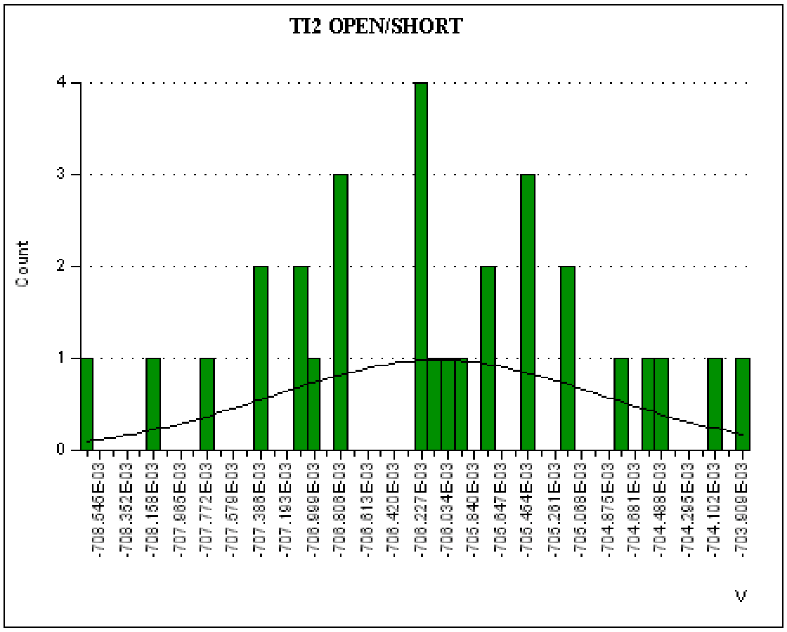
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=1.001, Test.Name=TI2 OPEN/SHORT



Statistics: (V)

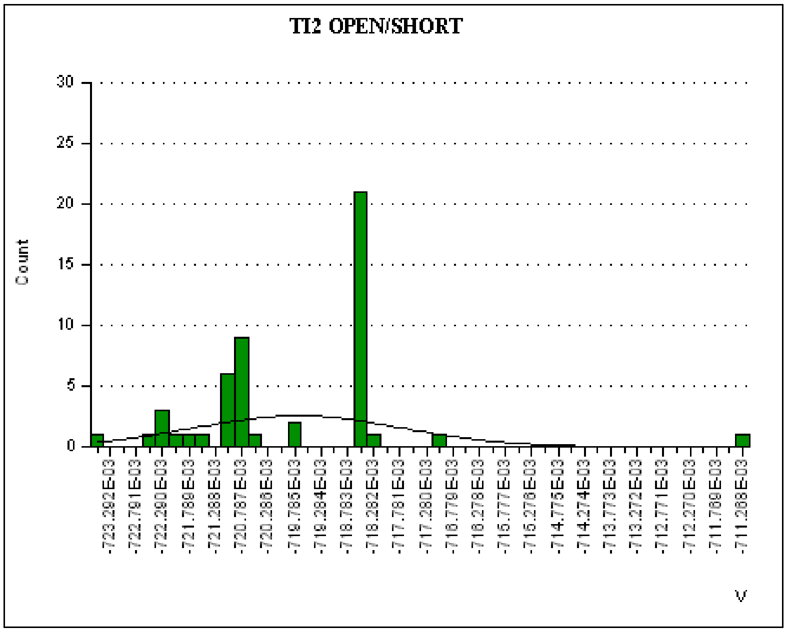
Min	-708.641E-03	**Skew**	-0.0941
Max	-703.909E-03	**StatHigh**	N/A
Mean	-706.133E-03	**StatLow**	N/A
StdDev	1.178E-03	**NWithinSpec**	N/A
25%	-706.962E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-702.599E-03	**90%**	-704.557E-03
		Range	4.733E-03
Mean-3*StdDev	-709.666E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=1.001, Test.Name=TI2 OPEN/SHORT



Statistics: (V)

Min	-723.542E-03	**StatLow**	N/A
Max	-711.268E-03	**NWithinSpec**	N/A
Mean	-719.759E-03	**NOutsideSpec**	N/A
StdDev	1.955E-03	**90%**	-718.542E-03
25%	-720.966E-03	**Range**	12.274E-03
Mean+3*StdDev	-713.895E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-725.622E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.4066		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

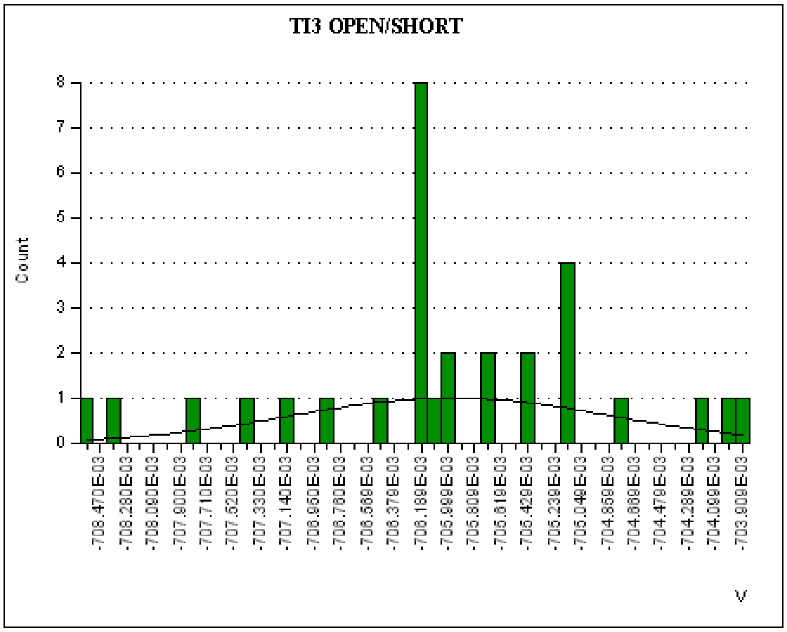
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=1.002, Test.Name=TI3 OPEN/SHORT



Statistics: (V)

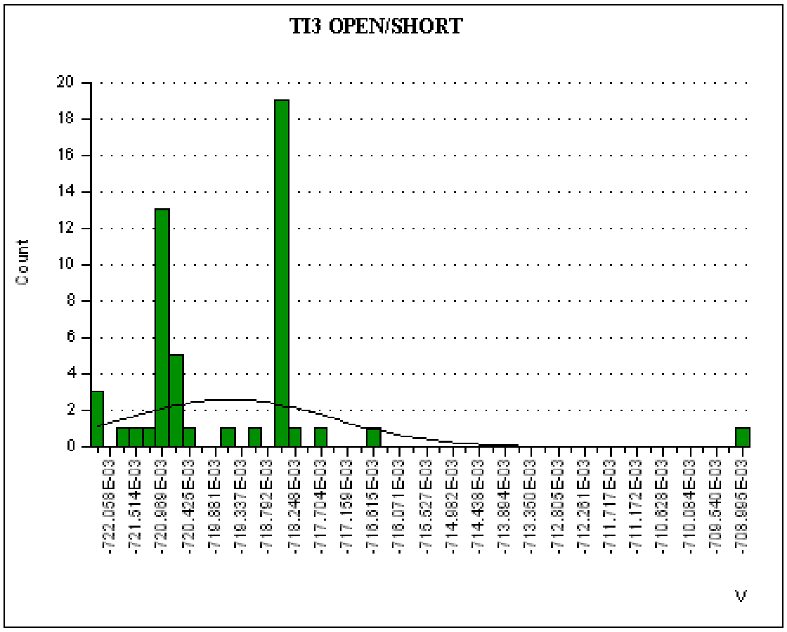
Min	-708.565E-03	**Skew**	-0.3210
Max	-703.909E-03	**StatHigh**	N/A
Mean	-706.000E-03	**StatLow**	N/A
StdDev	1.126E-03	**NWithinSpec**	N/A
25%	-706.199E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-702.622E-03	**90%**	-704.481E-03
		Range	4.656E-03
Mean-3*StdDev	-709.379E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=1.002, Test.Name=TI3 OPEN/SHORT



Statistics: (V)

Min	-722.330E-03	**StatLow**	N/A
Max	-708.995E-03	**NWithinSpec**	N/A
Mean	-719.615E-03	**NOutsideSpec**	N/A
StdDev	2.085E-03	**90%**	-718.466E-03
25%	-720.966E-03	**Range**	13.335E-03
Mean+3*StdDev	-713.361E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-725.869E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	2.6696		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

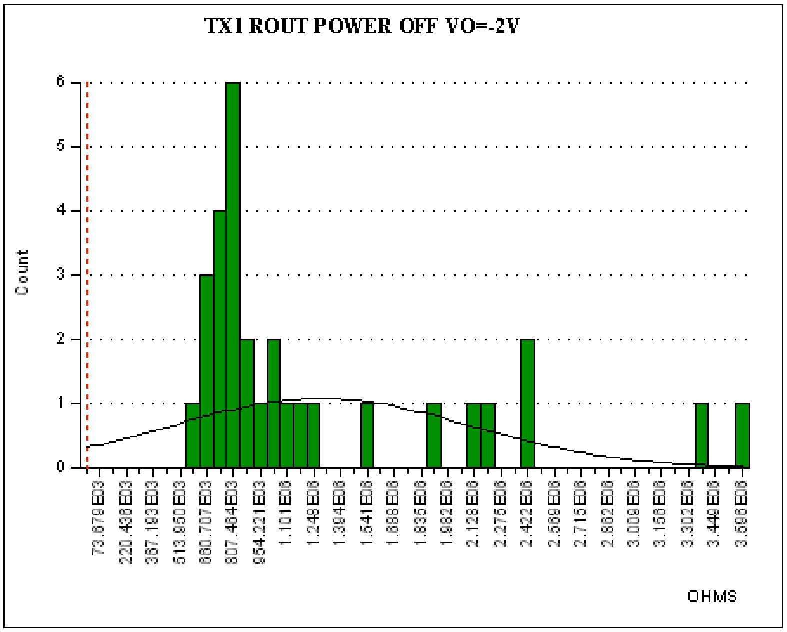
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=2.003, Test.Name=TX1 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

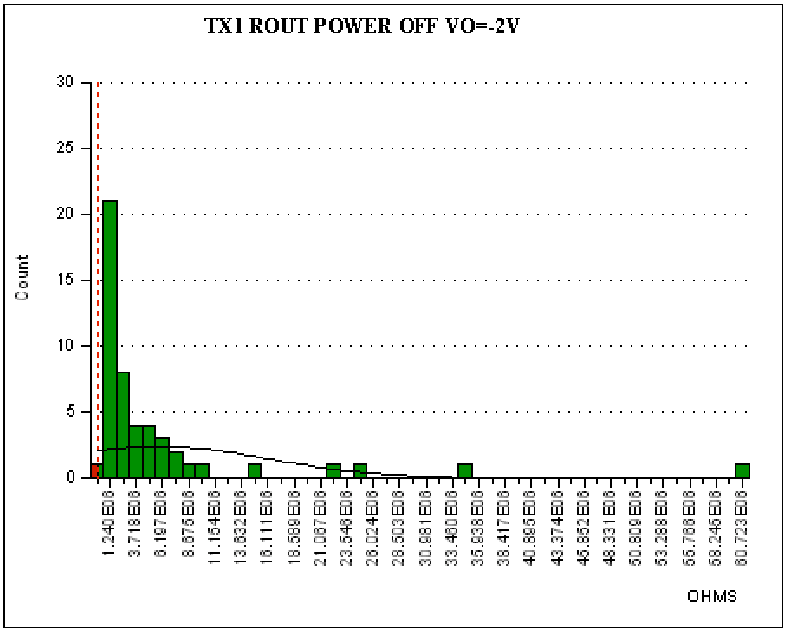
Min	584.059E03	**Skew**	1.6491
Max	3.596E06	**StatHigh**	N/A
Mean	1.274E06	**StatLow**	N/A
StdDev	813.700E03	**NWithinSpec**	30
25%	765.851E03	**NOutsideSpec**	0
Mean+3*StdDev	3.716E06	**90%**	2.434E06
		Range	3.012E06
Mean-3*StdDev	-1.167E06	**NOutsideSpec**	0
Cpk	0.5219		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.003, Test.Name=TX1 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

Min	600.985E03	**StatLow**	N/A
Max	60.723E06	**NWithinSpec**	50
Mean	5.799E06	**NOutsideSpec**	0
StdDev	10.253E06	**90%**	12.619E06
25%	1.290E06	**Range**	60.122E06
Mean+3*StdDev	36.557E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-24.959E06	**Cpl**	0.1885
		Cpu	N/A
Cpk	0.1885		
Skew	3.9180		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

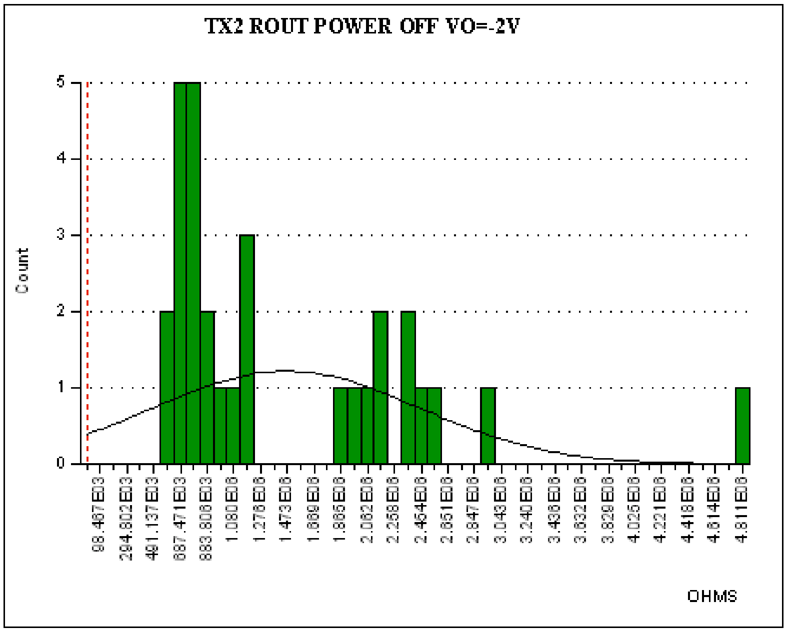
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=2.004, Test.Name=TX2 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

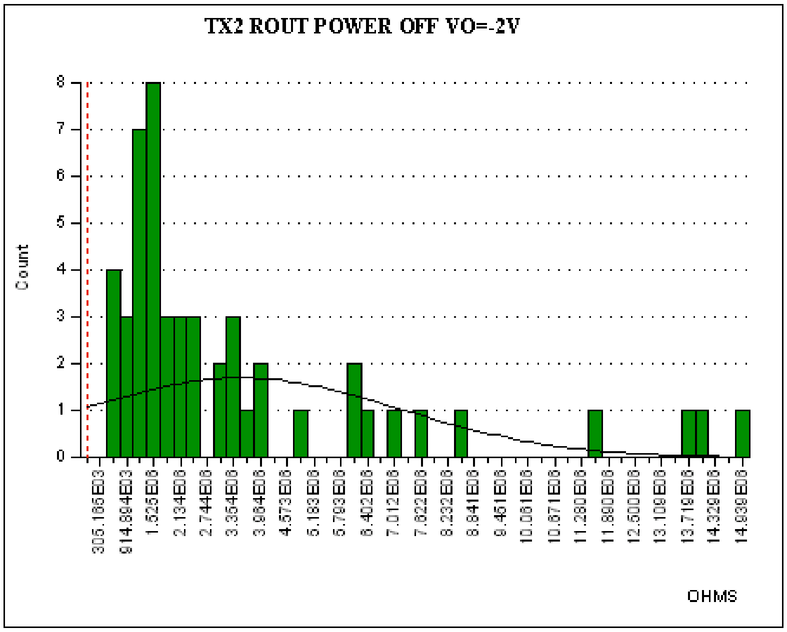
Min	620.906E03	**Skew**	1.6892
Max	4.811E06	**StatHigh**	N/A
Mean	1.448E06	**StatLow**	N/A
StdDev	962.824E03	**NWithinSpec**	30
25%	740.626E03	**NOutsideSpec**	0
Mean+3*StdDev	4.337E06	**90%**	2.515E06
		Range	4.190E06
Mean-3*StdDev	-1.440E06	**NOutsideSpec**	0
Cpk	0.5012		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=2.004, Test.Name=TX2 ROUT POWER OFF VO=-2V



Statistics: (OHMS)

Min	485.104E03	**StatLow**	N/A
Max	14.939E06	**NWithinSpec**	50
Mean	3.483E06	**NOutsideSpec**	0
StdDev	3.587E06	**90%**	8.145E06
25%	1.351E06	**Range**	14.454E06
Mean+3*StdDev	14.244E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-7.279E06	**Cpl**	0.3236
		Cpu	N/A
Cpk	0.3236		
Skew	1.9553		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

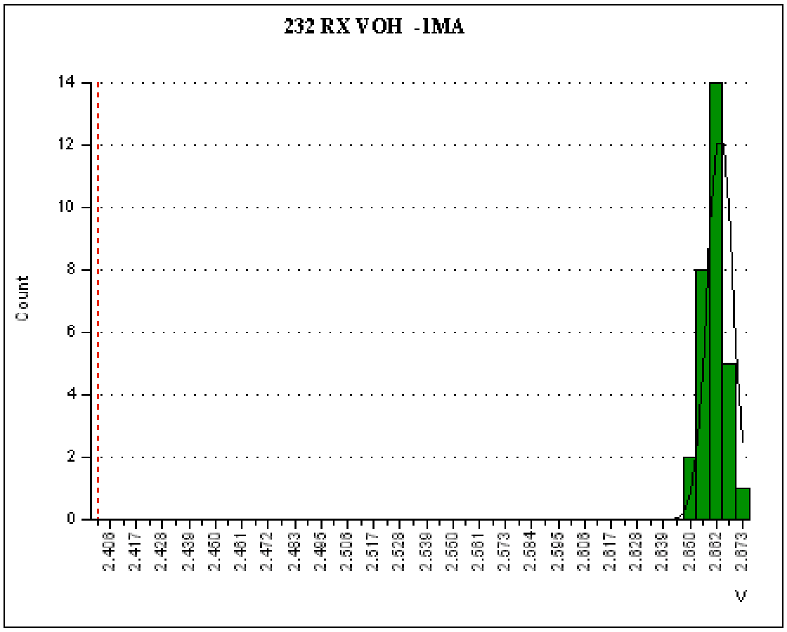
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.000, Test.Name=232 RX VOH -1MA



Statistics: (V)

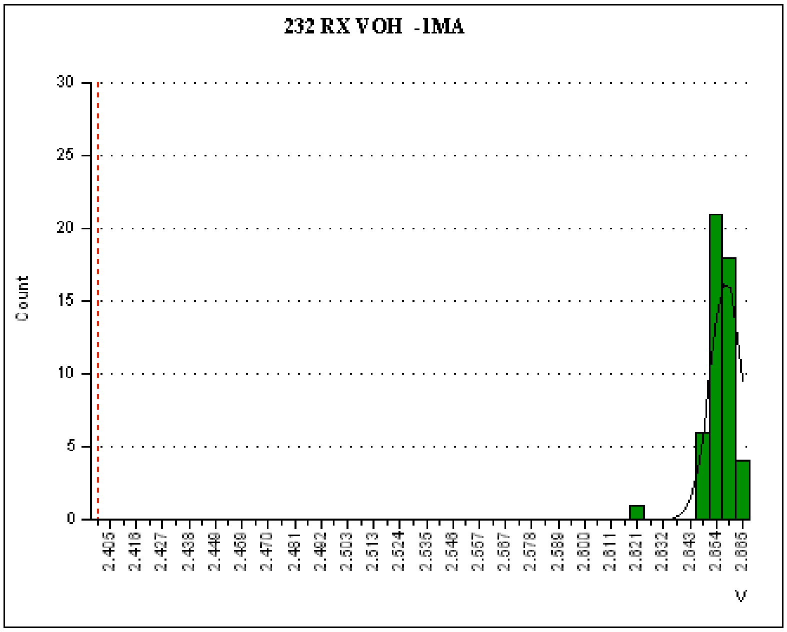
Min	2.650	**Skew**	0.0310
Max	2.673	**StatHigh**	N/A
Mean	2.660	**StatLow**	N/A
StdDev	5.351E-03	**NWithinSpec**	30
25%	2.656	**NOutsideSpec**	0
Mean+3*StdDev	2.676	**90%**	2.667
		Range	22.602E-03
Mean-3*StdDev	2.644	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.000, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.620	**StatLow**	N/A
Max	2.665	**NWithinSpec**	50
Mean	2.655	**NOutsideSpec**	0
StdDev	6.570E-03	**90%**	2.661
25%	2.652	**Range**	44.834E-03
Mean+3*StdDev	2.675	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.635	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-3.1018		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

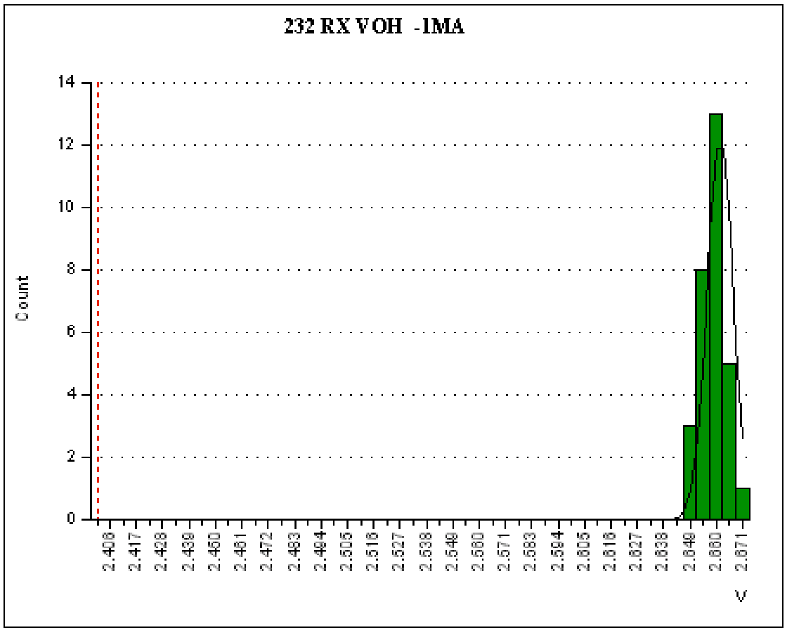
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.001, Test.Name=232 RX VOH -1MA



Statistics: (V)

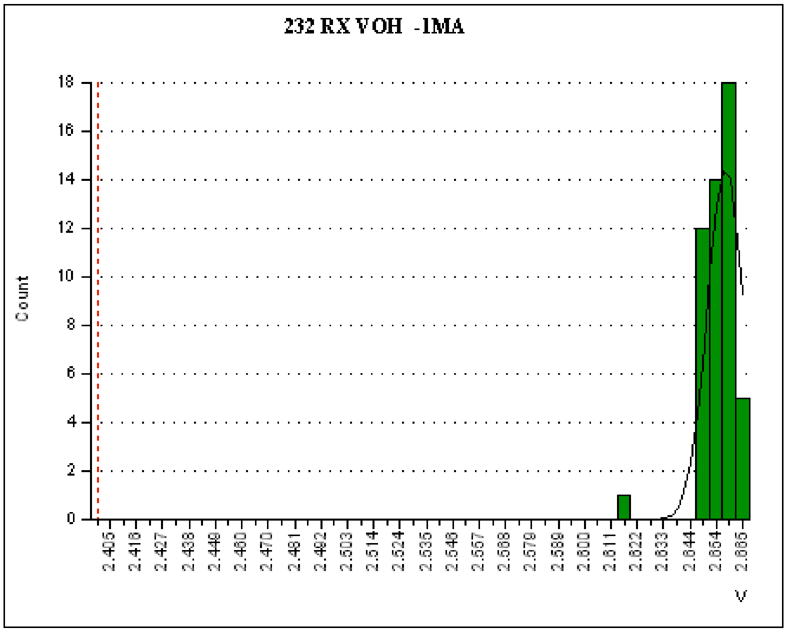
Min	2.648	**Skew**	-0.2501
Max	2.671	**StatHigh**	N/A
Mean	2.659	**StatLow**	N/A
StdDev	5.391E-03	**NWithinSpec**	30
25%	2.655	**NOutsideSpec**	0
Mean+3*StdDev	2.675	**90%**	2.665
		Range	23.428E-03
Mean-3*StdDev	2.643	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.001, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.617	**StatLow**	N/A
Max	2.665	**NWithinSpec**	50
Mean	2.656	**NOutsideSpec**	0
StdDev	7.459E-03	**90%**	2.662
25%	2.651	**Range**	48.135E-03
Mean+3*StdDev	2.678	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.633	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-2.7714		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

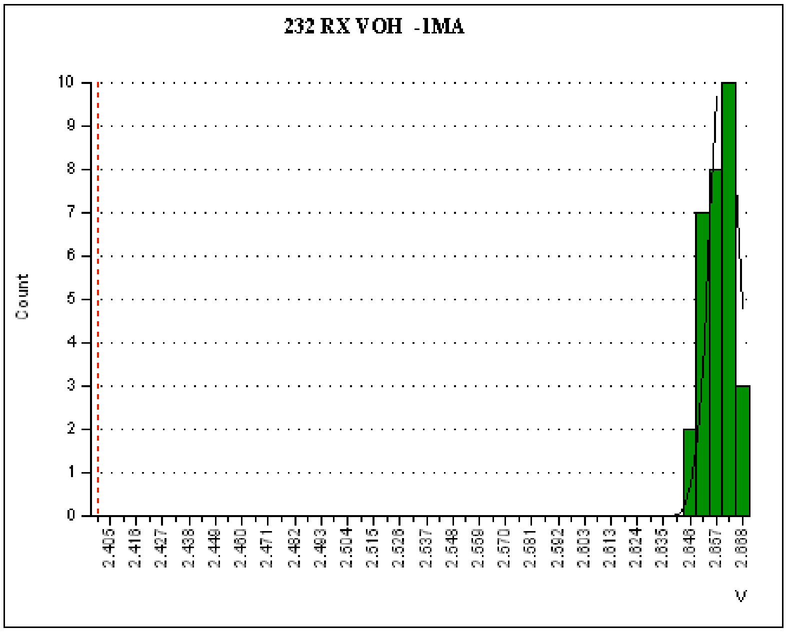
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.002, Test.Name=232 RX VOH -1MA



Statistics: (V)

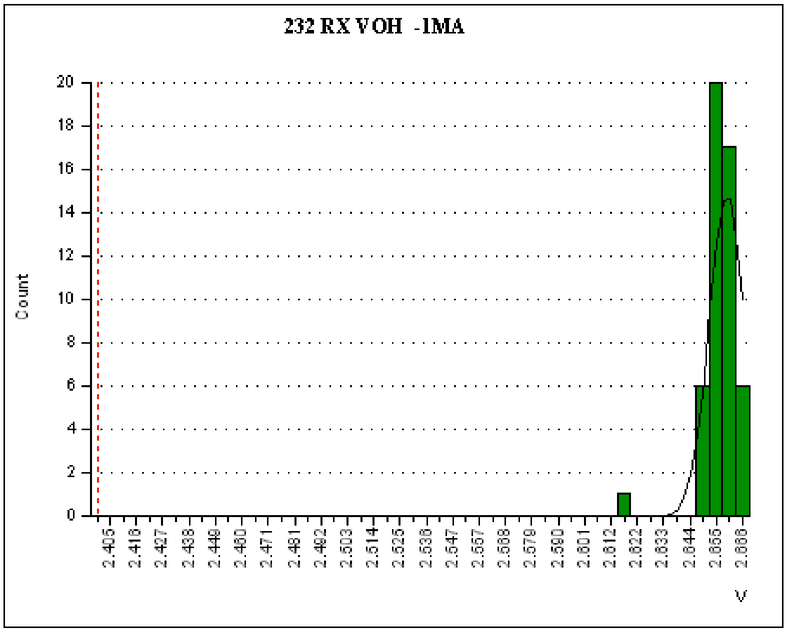
Min	2.646	**Skew**	-0.2336
Max	2.668	**StatHigh**	N/A
Mean	2.658	**StatLow**	N/A
StdDev	5.886E-03	**NWithinSpec**	30
25%	2.653	**NOutsideSpec**	0
Mean+3*StdDev	2.676	**90%**	2.665
		Range	22.244E-03
Mean-3*StdDev	2.640	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.002, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.616	**StatLow**	N/A
Max	2.666	**NWithinSpec**	50
Mean	2.657	**NOutsideSpec**	0
StdDev	7.298E-03	**90%**	2.664
25%	2.654	**Range**	49.561E-03
Mean+3*StdDev	2.679	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.635	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-3.4448		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

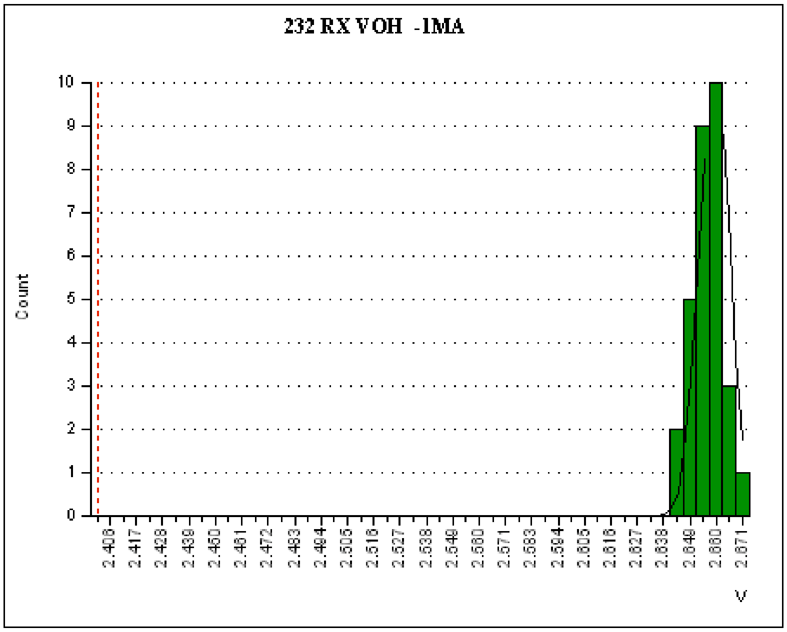
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.003, Test.Name=232 RX VOH -1MA



Statistics: (V)

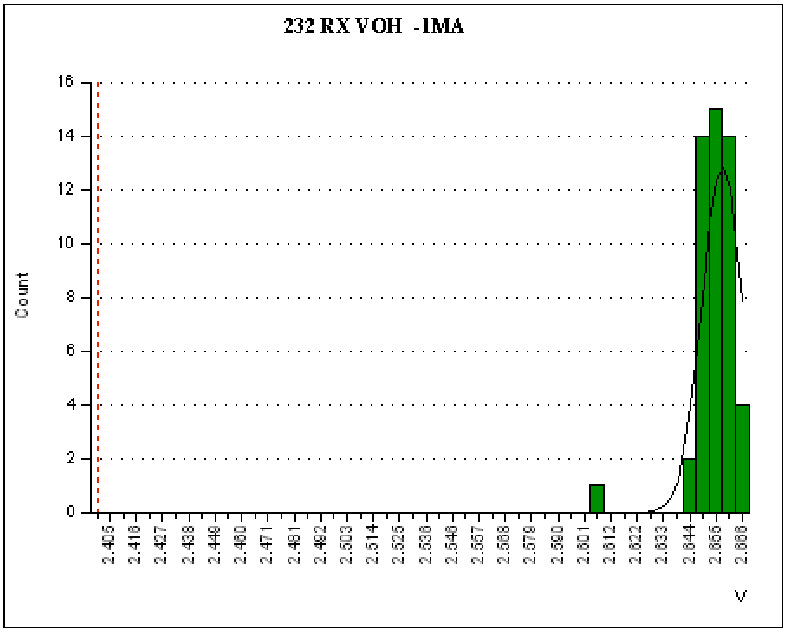
Min	2.644	**Skew**	0.1081
Max	2.671	**StatHigh**	N/A
Mean	2.656	**StatLow**	N/A
StdDev	6.311E-03	**NWithinSpec**	30
25%	2.652	**NOutsideSpec**	0
Mean+3*StdDev	2.675	**90%**	2.665
		Range	27.481E-03
Mean-3*StdDev	2.638	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.003, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.608	**StatLow**	N/A
Max	2.666	**NWithinSpec**	50
Mean	2.655	**NOutsideSpec**	0
StdDev	8.418E-03	**90%**	2.662
25%	2.651	**Range**	57.539E-03
Mean+3*StdDev	2.680	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.630	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-3.4485		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

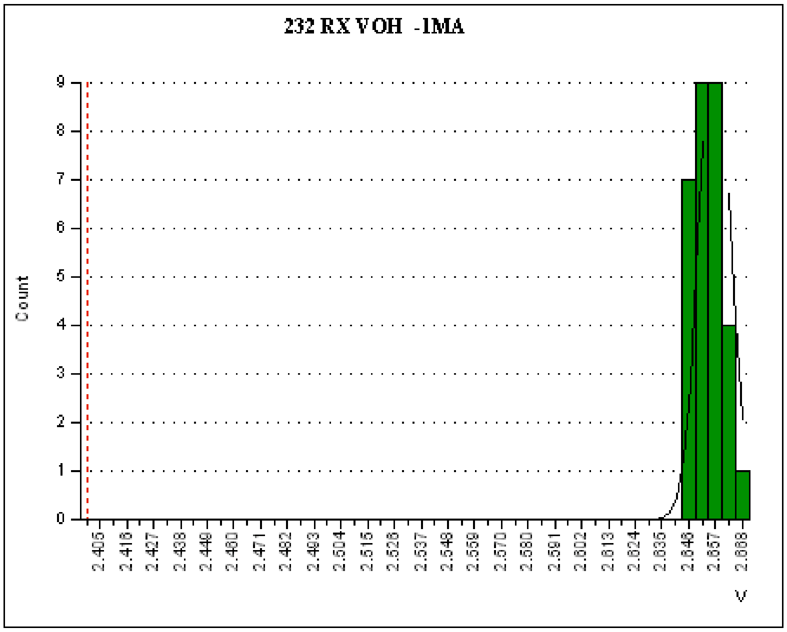
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.004, Test.Name=232 RX VOH -1MA



Statistics: (V)

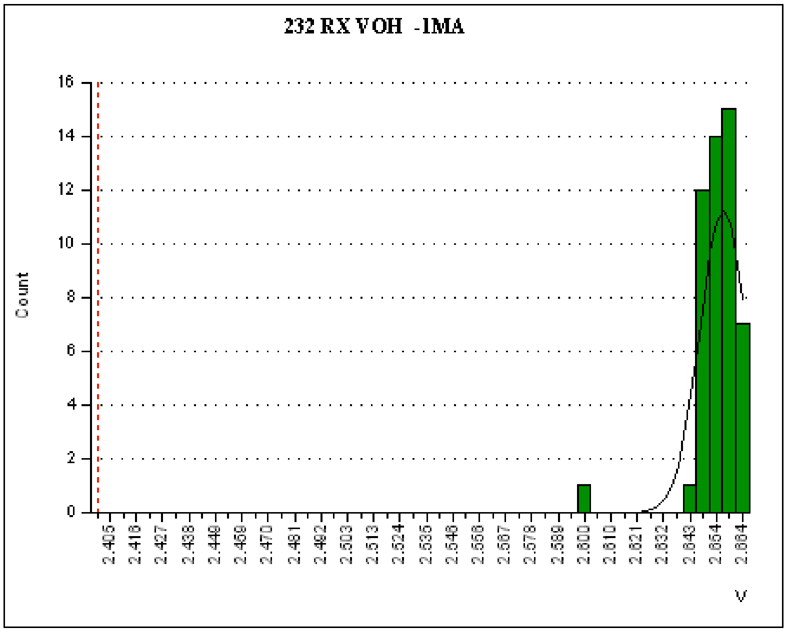
Min	2.644	**Skew**	0.5363
Max	2.668	**StatHigh**	N/A
Mean	2.654	**StatLow**	N/A
StdDev	6.253E-03	**NWithinSpec**	30
25%	2.649	**NOutsideSpec**	0
Mean+3*StdDev	2.673	**90%**	2.664
		Range	23.553E-03
Mean-3*StdDev	2.635	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.004, Test.Name=232 RX VOH -1MA



Statistics: (V)

Min	2.599	**StatLow**	N/A
Max	2.664	**NWithinSpec**	50
Mean	2.654	**NOutsideSpec**	0
StdDev	9.594E-03	**90%**	2.663
25%	2.650	**Range**	65.757E-03
Mean+3*StdDev	2.683	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.625	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-3.9199		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

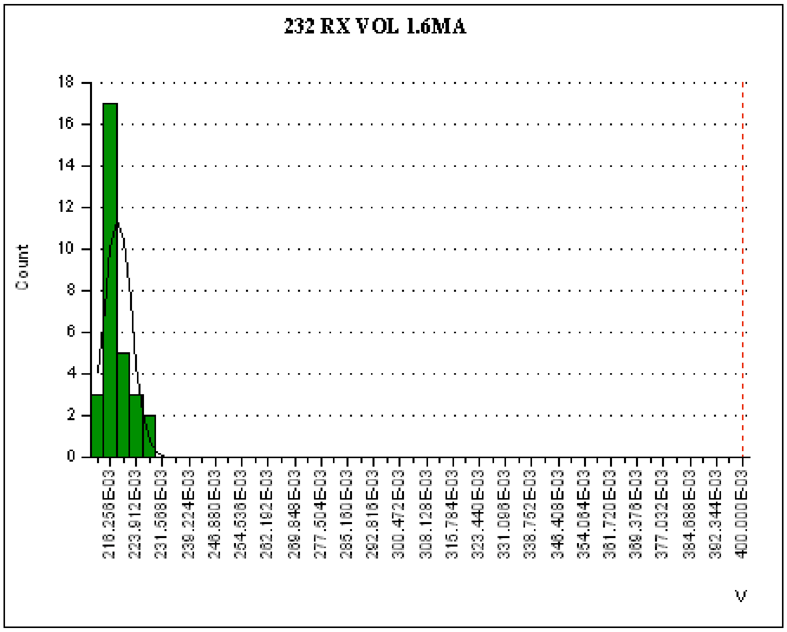
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.005, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

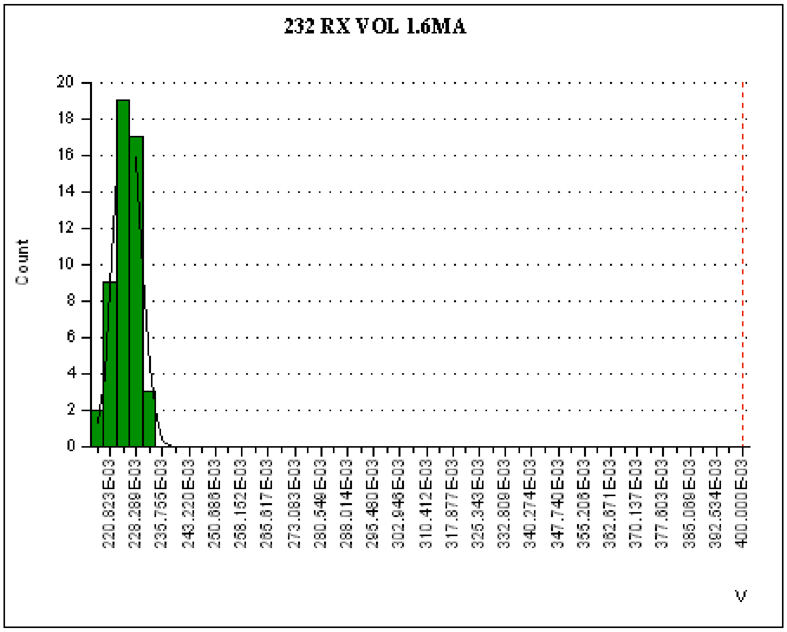
Min	212.428E-03	**Skew**	0.8727
Max	227.051E-03	**StatHigh**	N/A
Mean	218.167E-03	**StatLow**	N/A
StdDev	4.003E-03	**NWithinSpec**	30
25%	215.237E-03	**NOutsideSpec**	0
Mean+3*StdDev	230.176E-03	**90%**	224.708E-03
		Range	14.623E-03
Mean-3*StdDev	206.158E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.005, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	217.090E-03	**StatLow**	N/A
Max	231.349E-03	**NWithinSpec**	50
Mean	225.433E-03	**NOutsideSpec**	0
StdDev	3.549E-03	**90%**	229.966E-03
25%	223.017E-03	**Range**	14.259E-03
Mean+3*StdDev	236.081E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	214.785E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.2518		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

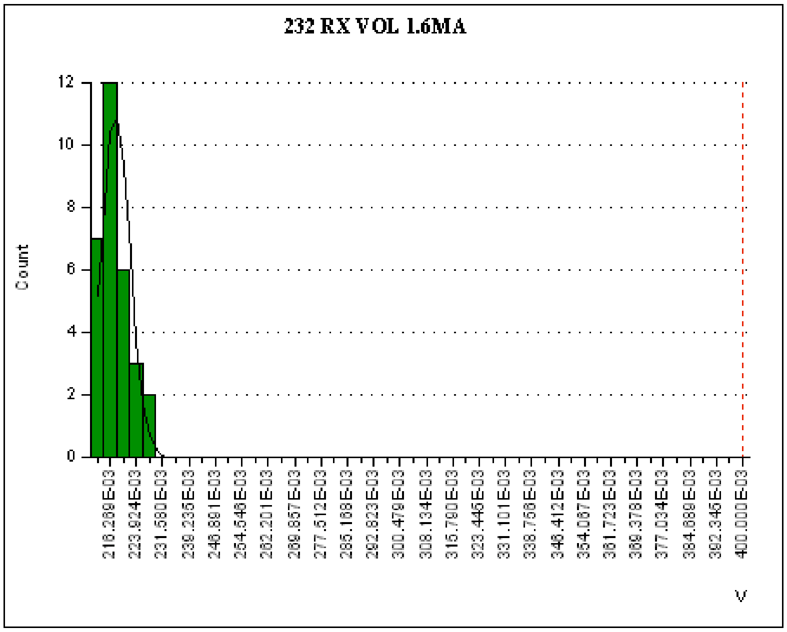
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.006, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

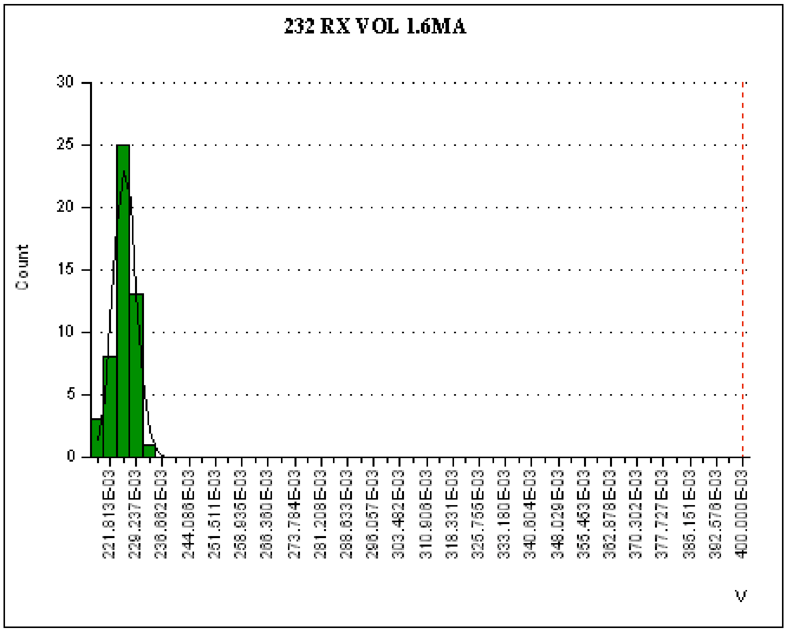
Min	212.441E-03	**Skew**	1.0065
Max	228.347E-03	**StatHigh**	N/A
Mean	217.557E-03	**StatLow**	N/A
StdDev	4.166E-03	**NWithinSpec**	30
25%	214.652E-03	**NOutsideSpec**	0
Mean+3*StdDev	230.056E-03	**90%**	224.212E-03
		Range	15.906E-03
Mean-3*StdDev	205.057E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.006, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	218.100E-03	**StatLow**	N/A
Max	231.437E-03	**NWithinSpec**	50
Mean	225.655E-03	**NOutsideSpec**	0
StdDev	3.211E-03	**90%**	229.897E-03
25%	224.304E-03	**Range**	13.337E-03
Mean+3*StdDev	235.288E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	216.022E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.2367		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

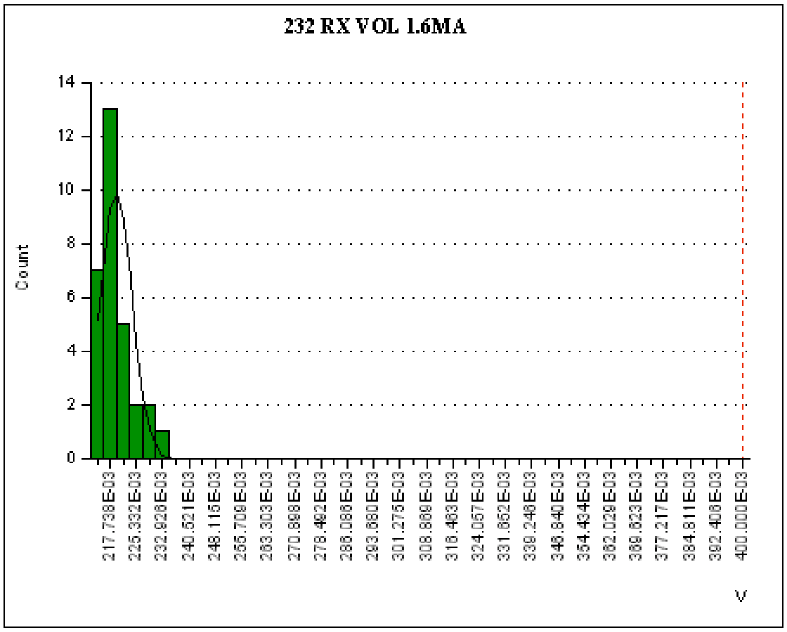
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.007, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

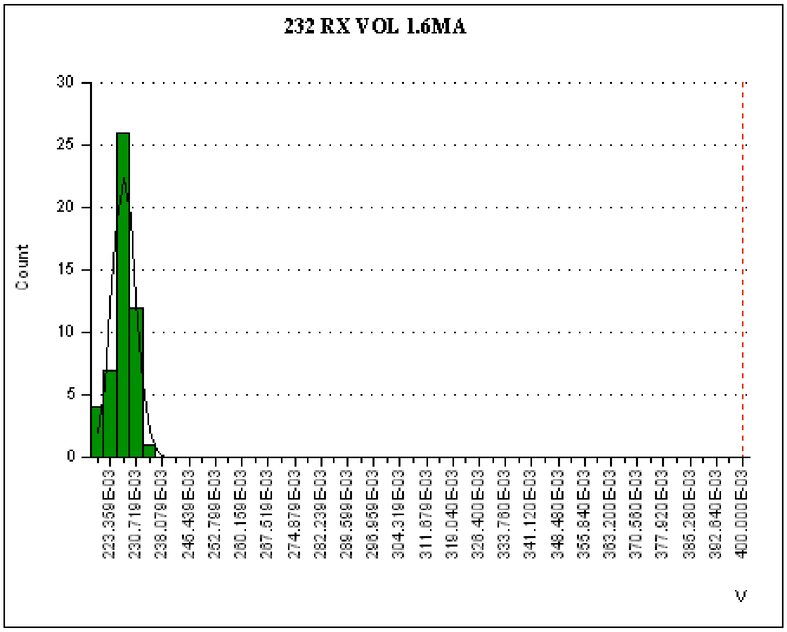
Min	213.941E-03	**Skew**	1.2633
Max	231.878E-03	**StatHigh**	N/A
Mean	219.185E-03	**StatLow**	N/A
StdDev	4.587E-03	**NWithinSpec**	30
25%	216.190E-03	**NOutsideSpec**	0
Mean+3*StdDev	232.947E-03	**90%**	226.556E-03
		Range	17.938E-03
Mean-3*StdDev	205.422E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.007, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	219.679E-03	**StatLow**	N/A
Max	232.750E-03	**NWithinSpec**	50
Mean	226.943E-03	**NOutsideSpec**	0
StdDev	3.291E-03	**90%**	231.734E-03
25%	225.459E-03	**Range**	13.071E-03
Mean+3*StdDev	236.817E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	217.068E-03	**Cpl**	N/A
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.0915		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

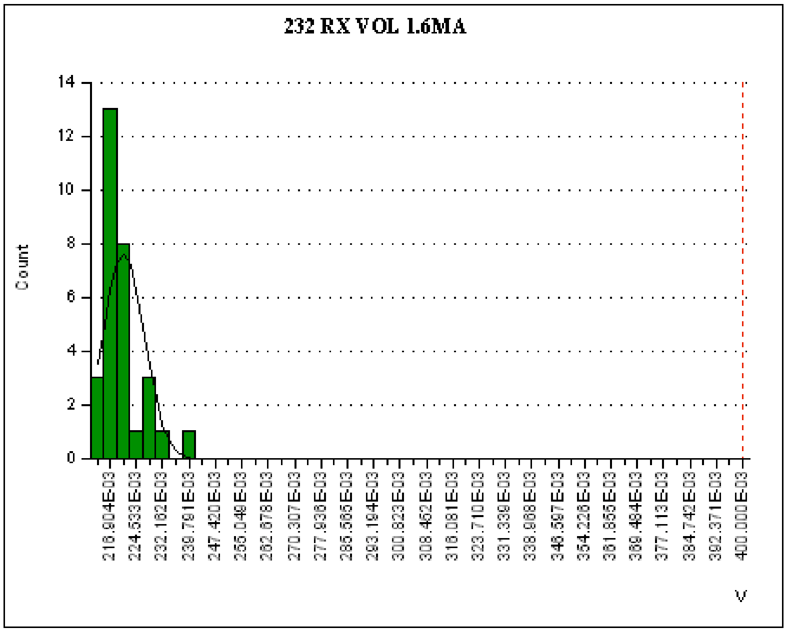
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.008, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

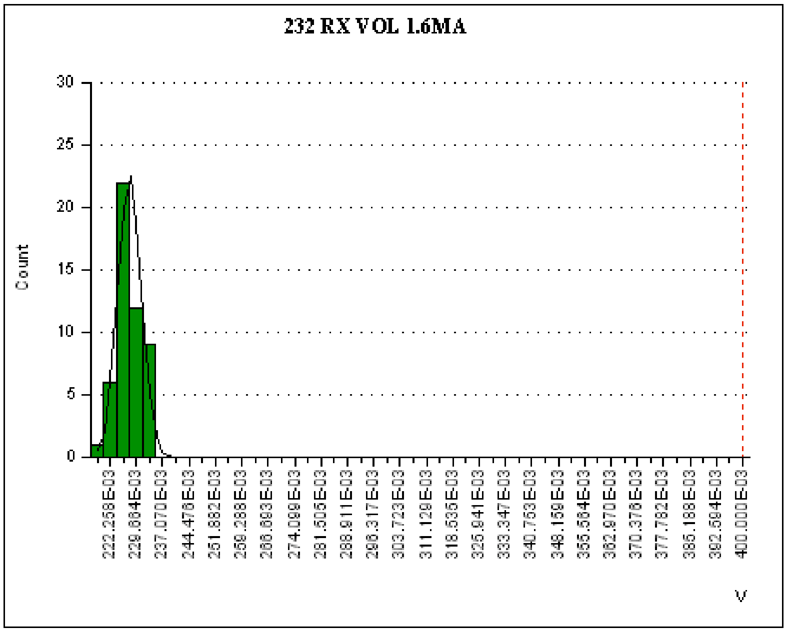
Min	213.089E-03	**Skew**	1.7903
Max	241.370E-03	**StatHigh**	N/A
Mean	220.519E-03	**StatLow**	N/A
StdDev	5.992E-03	**NWithinSpec**	30
25%	216.788E-03	**NOutsideSpec**	0
Mean+3*StdDev	238.495E-03	**90%**	228.468E-03
		Range	28.281E-03
Mean-3*StdDev	202.543E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.008, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	218.555E-03	**StatLow**	N/A
Max	232.574E-03	**NWithinSpec**	50
Mean	227.459E-03	**NOutsideSpec**	0
StdDev	3.269E-03	**90%**	231.841E-03
25%	225.257E-03	**Range**	14.019E-03
Mean+3*StdDev	237.266E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	217.653E-03	**Cpl**	N/A
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.2348		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

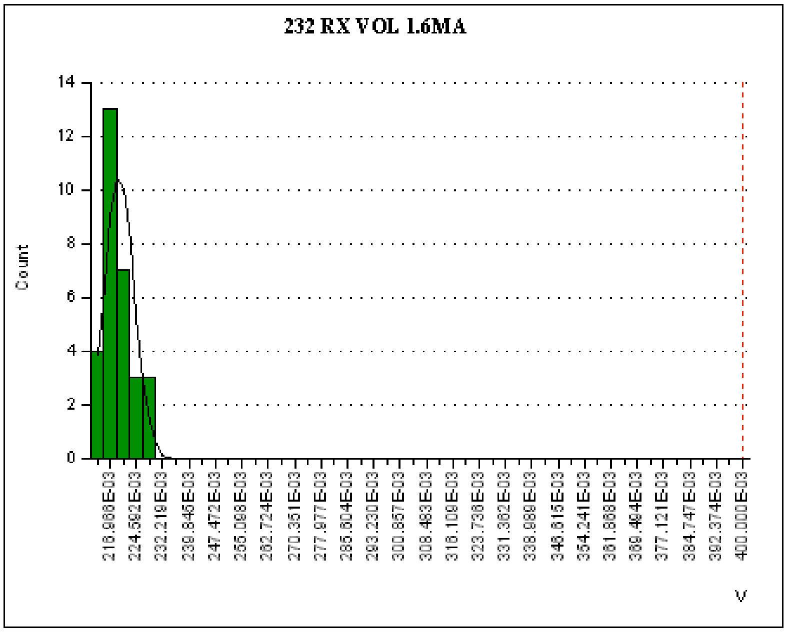
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.009, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

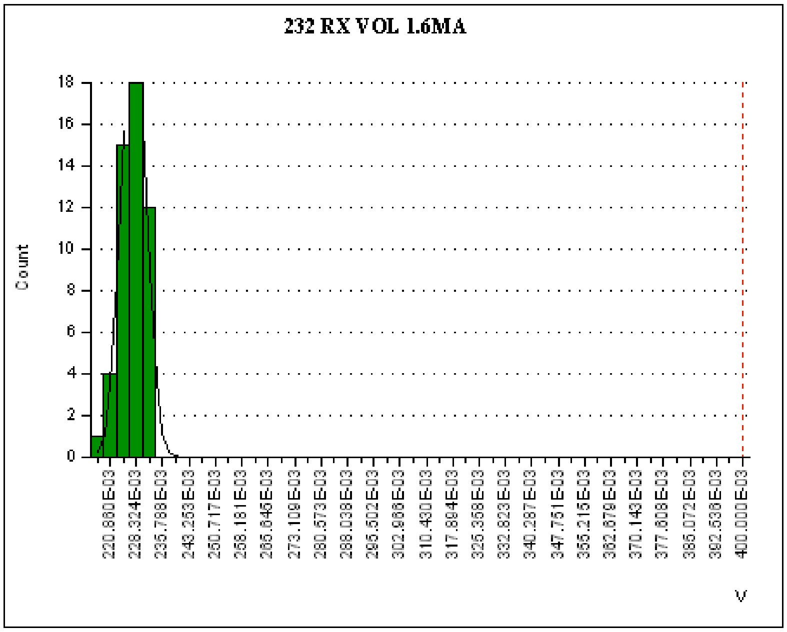
Min	213.153E-03	**Skew**	0.6989
Max	228.385E-03	**StatHigh**	N/A
Mean	219.293E-03	**StatLow**	N/A
StdDev	4.334E-03	**NWithinSpec**	30
25%	216.051E-03	**NOutsideSpec**	0
Mean+3*StdDev	232.296E-03	**90%**	226.365E-03
		Range	15.233E-03
Mean-3*StdDev	206.290E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.009, Test.Name=232 RX VOL 1.6MA



Statistics: (V)

Min	217.128E-03	**StatLow**	N/A
Max	232.851E-03	**NWithinSpec**	50
Mean	227.237E-03	**NOutsideSpec**	0
StdDev	3.365E-03	**90%**	231.563E-03
25%	225.118E-03	**Range**	15.723E-03
Mean+3*StdDev	237.332E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	217.141E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.5157		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

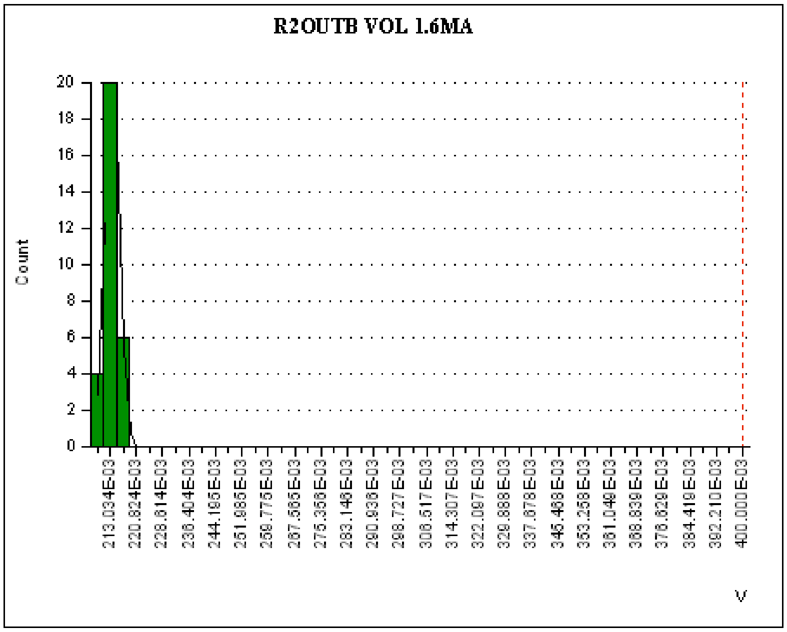
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.010, Test.Name=R2OUTB VOL 1.6MA



Statistics: (V)

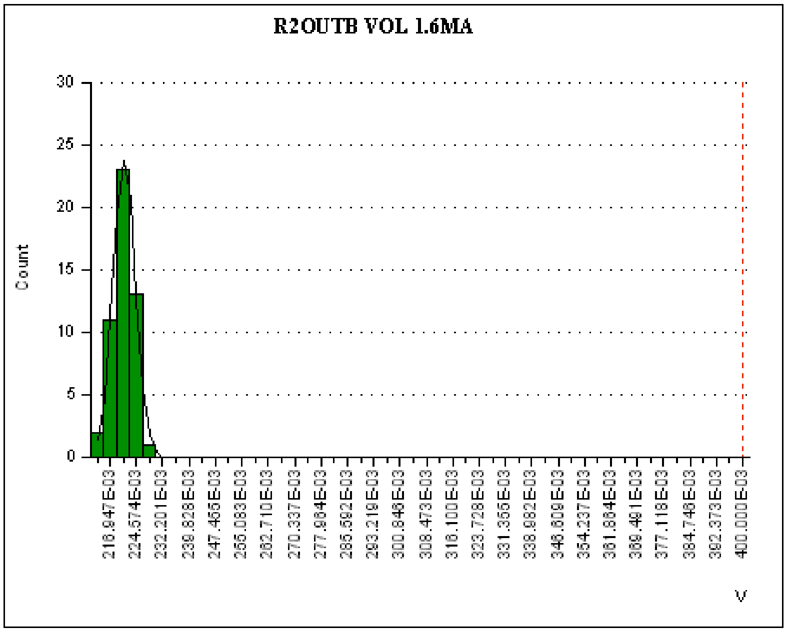
Min	209.139E-03	**Skew**	-0.1281
Max	217.268E-03	**StatHigh**	N/A
Mean	213.321E-03	**StatLow**	N/A
StdDev	2.059E-03	**NWithinSpec**	30
25%	211.945E-03	**NOutsideSpec**	0
Mean+3*StdDev	219.498E-03	**90%**	215.841E-03
		Range	8.130E-03
Mean-3*StdDev	207.144E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.010, Test.Name=R2OUTB VOL 1.6MA



Statistics: (V)

Min	213.133E-03	**StatLow**	N/A
Max	226.571E-03	**NWithinSpec**	50
Mean	220.776E-03	**NOutsideSpec**	0
StdDev	3.197E-03	**90%**	225.156E-03
25%	218.328E-03	**Range**	13.438E-03
Mean+3*StdDev	230.368E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	211.185E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.2137		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

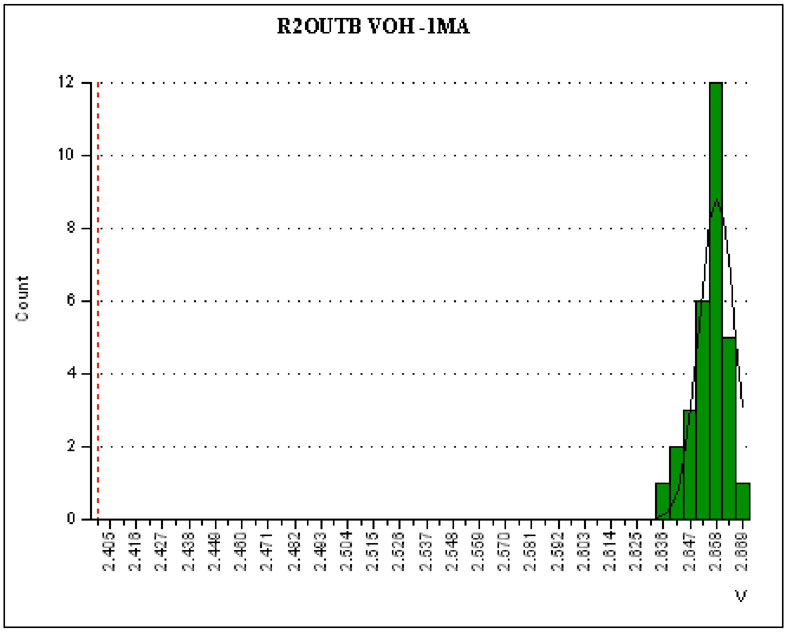
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=3.011, Test.Name=R2OUTB VOH -1MA



Statistics: (V)

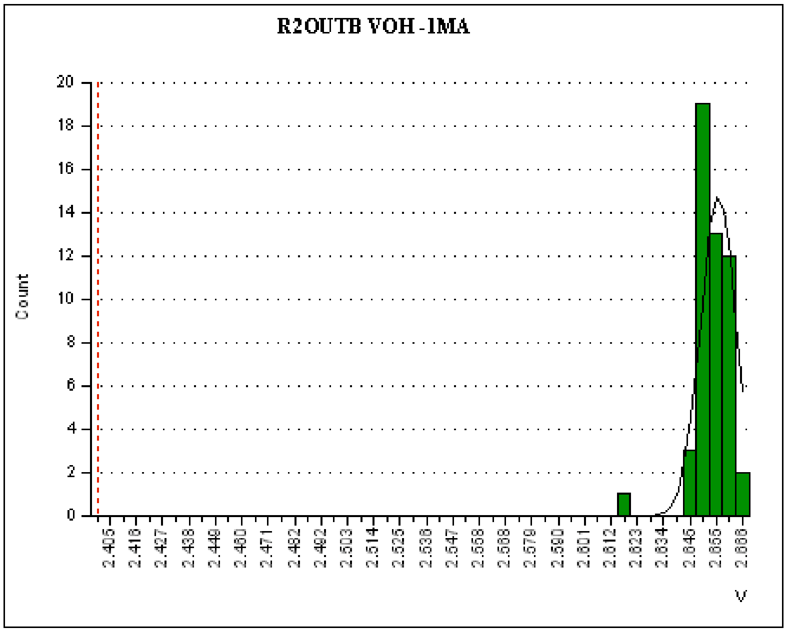
Min	2.636	**Skew**	-0.9446
Max	2.669	**StatHigh**	N/A
Mean	2.656	**StatLow**	N/A
StdDev	7.458E-03	**NWithinSpec**	30
25%	2.652	**NOutsideSpec**	0
Mean+3*StdDev	2.678	**90%**	2.663
		Range	32.776E-03
Mean-3*StdDev	2.633	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=3.011, Test.Name=R2OUTB VOH -1MA



Statistics: (V)

Min	2.617	**StatLow**	N/A
Max	2.666	**NWithinSpec**	50
Mean	2.654	**NOutsideSpec**	0
StdDev	7.358E-03	**90%**	2.660
25%	2.649	**Range**	49.499E-03
Mean+3*StdDev	2.676	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	2.631	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-2.4422		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

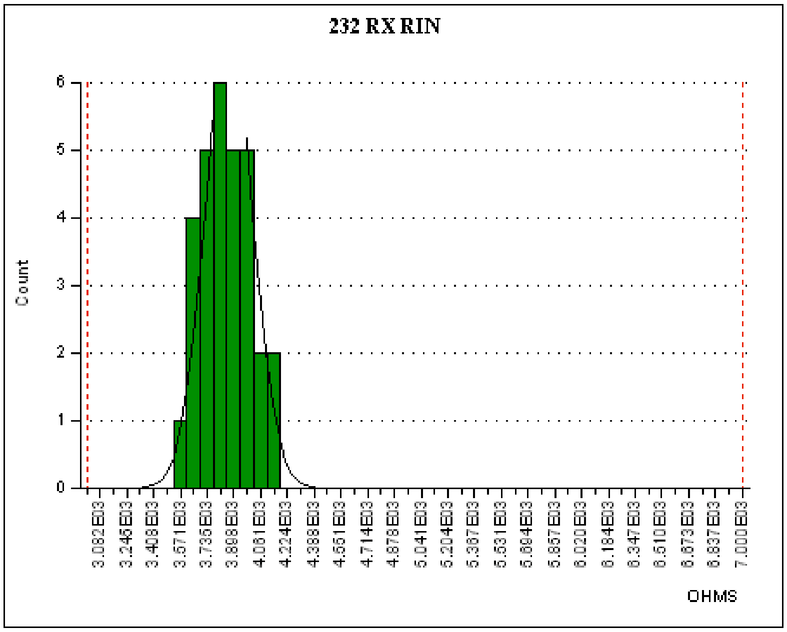
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=4.000, Test.Name=232 RX RIN



Statistics: (OHMS)

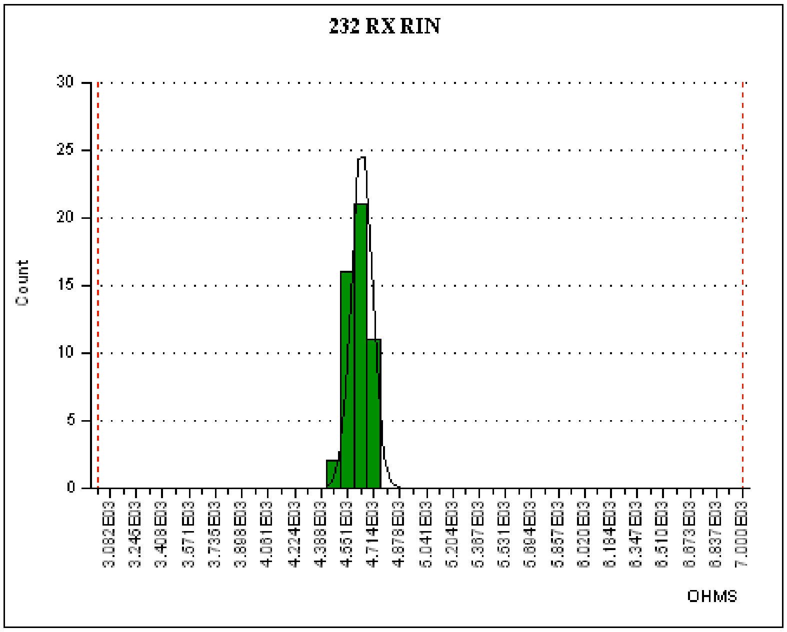
Min	3.609E03	**Skew**	0.1988
Max	4.141E03	**StatHigh**	N/A
Mean	3.855E03	**StatLow**	N/A
StdDev	144.773	**NWithinSpec**	30
25%	3.730E03	**NOutsideSpec**	0
Mean+3*StdDev	4.289E03	**90%**	4.046E03
		Range	532.218
Mean-3*StdDev	3.421E03	**NOutsideSpec**	0
Cpk	1.9682		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.000, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.464E03	**StatLow**	N/A
Max	4.729E03	**NWithinSpec**	50
Mean	4.620E03	**NOutsideSpec**	0
StdDev	63.431	**90%**	4.709E03
25%	4.578E03	**Range**	264.535
Mean+3*StdDev	4.811E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.430E03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.2647		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

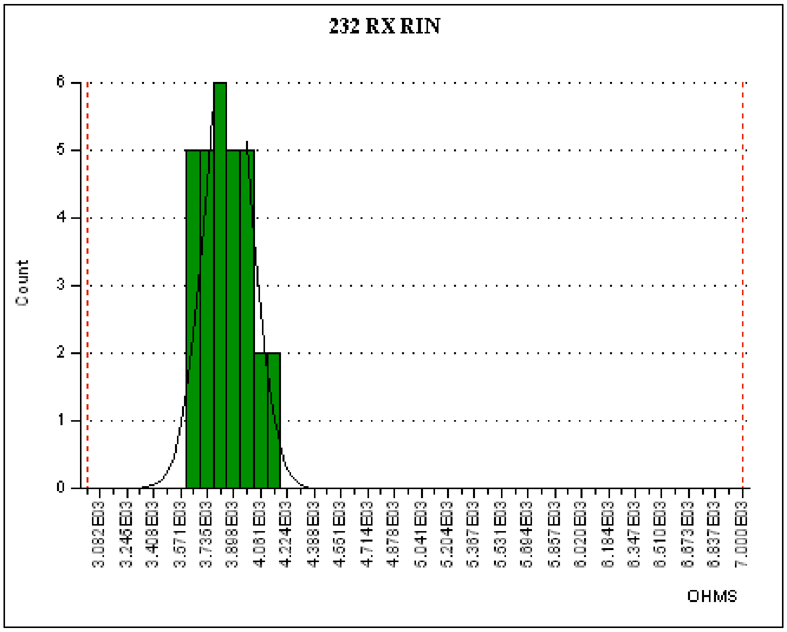
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=4.001, Test.Name=232 RX RIN



Statistics: (OHMS)

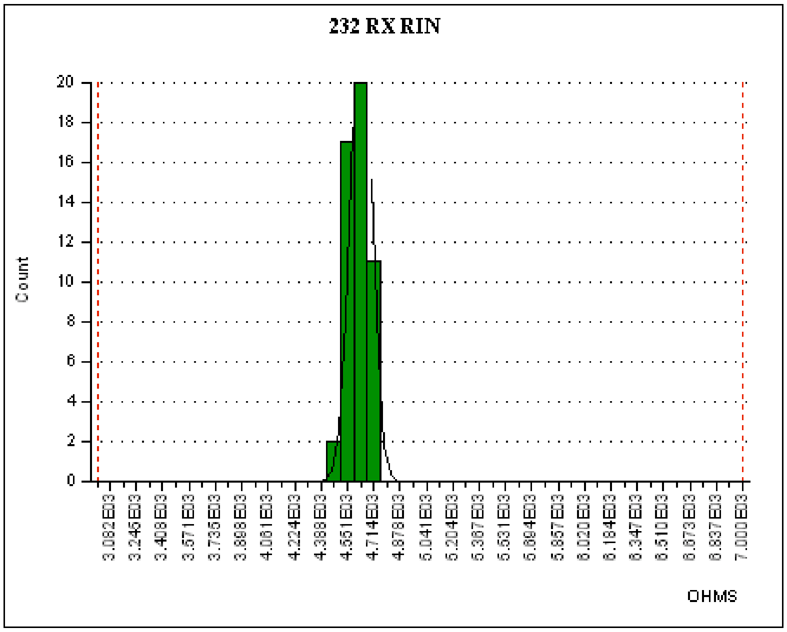
Min	3.632E03	**Skew**	0.2661
Max	4.132E03	**StatHigh**	N/A
Mean	3.852E03	**StatLow**	N/A
StdDev	142.446	**NWithinSpec**	30
25%	3.733E03	**NOutsideSpec**	0
Mean+3*StdDev	4.279E03	**90%**	4.049E03
		Range	500.223
Mean-3*StdDev	3.424E03	**NOutsideSpec**	0
Cpk	1.9932		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.001, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.449E03	**StatLow**	N/A
Max	4.717E03	**NWithinSpec**	50
Mean	4.615E03	**NOutsideSpec**	0
StdDev	62.251	**90%**	4.699E03
25%	4.577E03	**Range**	267.980
Mean+3*StdDev	4.802E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.428E03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.4378		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

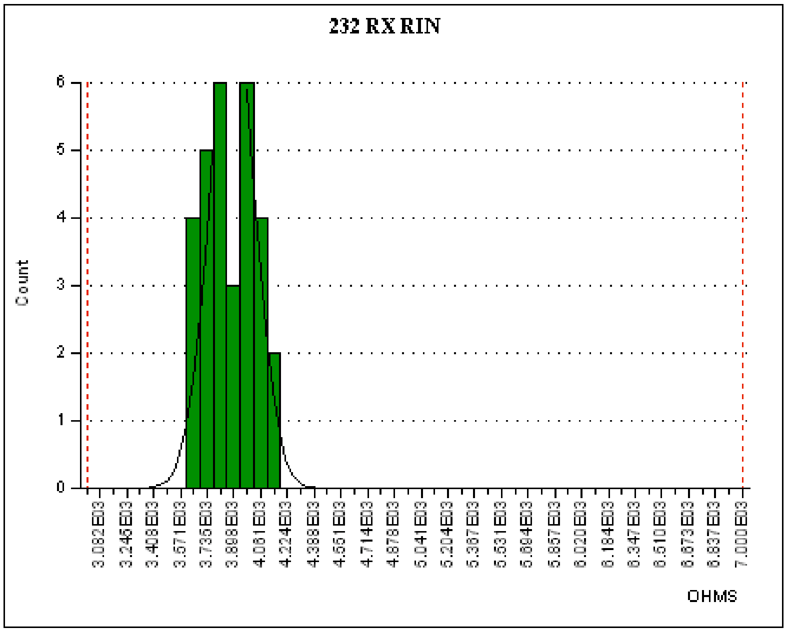
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=4.002, Test.Name=232 RX RIN



Statistics: (OHMS)

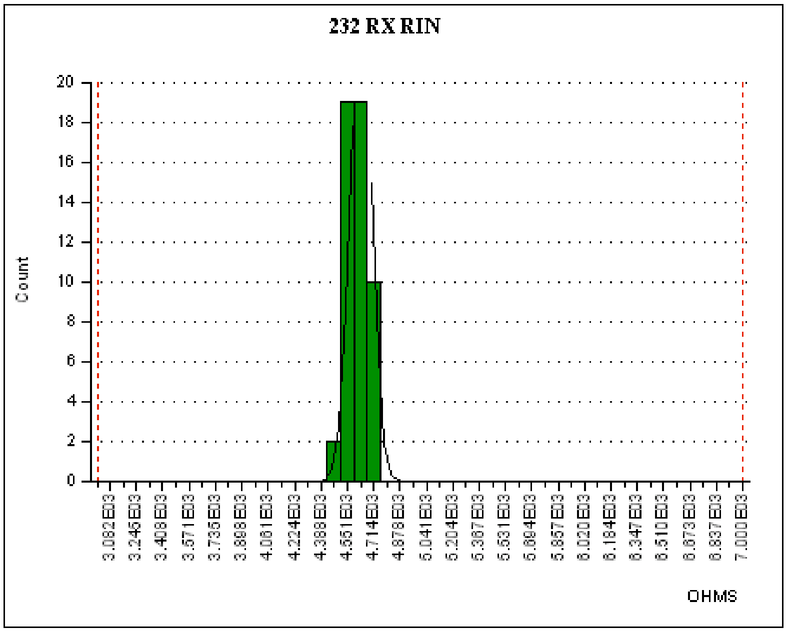
Min	3.654E03	**Skew**	0.1583
Max	4.130E03	**StatHigh**	N/A
Mean	3.876E03	**StatLow**	N/A
StdDev	137.030	**NWithinSpec**	30
25%	3.765E03	**NOutsideSpec**	0
Mean+3*StdDev	4.287E03	**90%**	4.051E03
		Range	475.525
Mean-3*StdDev	3.465E03	**NOutsideSpec**	0
Cpk	2.1305		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.002, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.454E03	**StatLow**	N/A
Max	4.721E03	**NWithinSpec**	50
Mean	4.614E03	**NOutsideSpec**	0
StdDev	63.934	**90%**	4.699E03
25%	4.579E03	**Range**	267.090
Mean+3*StdDev	4.806E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.422E03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.3834		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

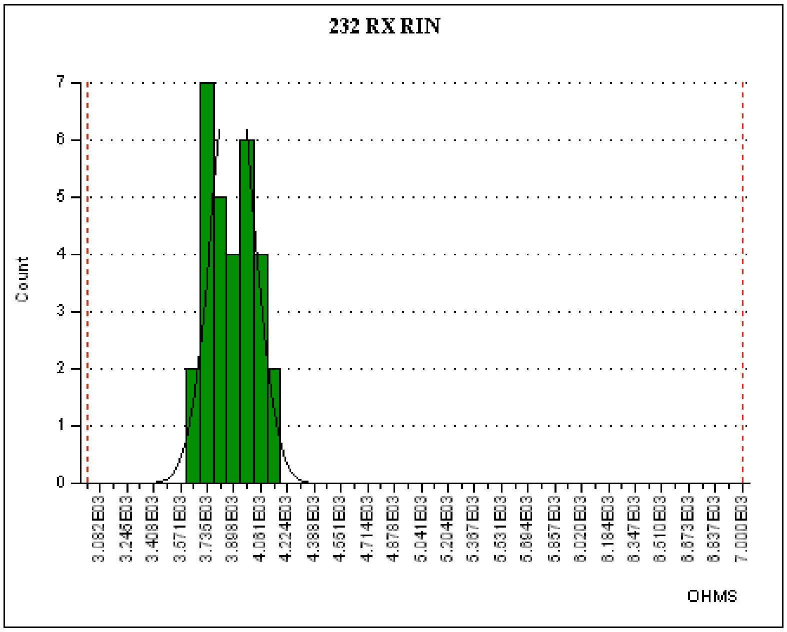
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=4.003, Test.Name=232 RX RIN



Statistics: (OHMS)

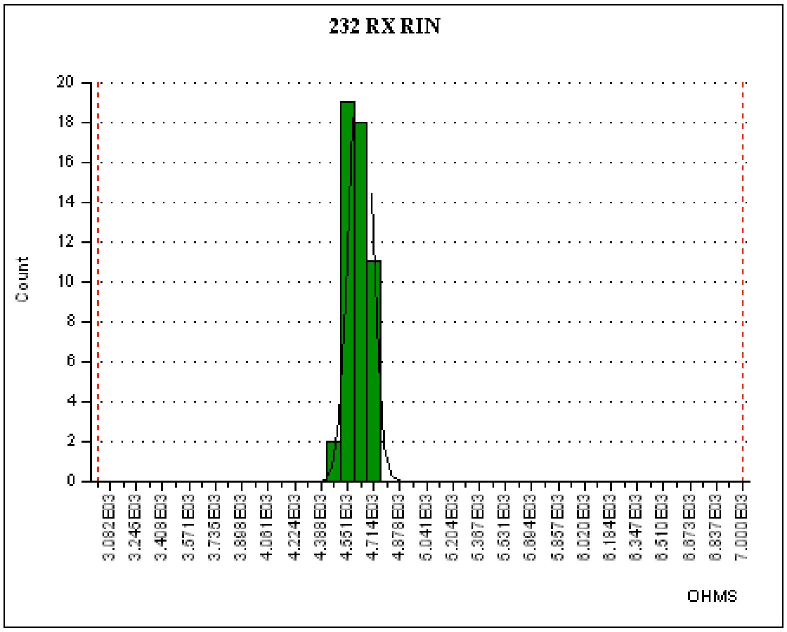
Min	3.669E03	**Skew**	0.1980
Max	4.120E03	**StatHigh**	N/A
Mean	3.880E03	**StatLow**	N/A
StdDev	131.225	**NWithinSpec**	30
25%	3.771E03	**NOutsideSpec**	0
Mean+3*StdDev	4.274E03	**90%**	4.057E03
		Range	451.540
Mean-3*StdDev	3.486E03	**NOutsideSpec**	0
Cpk	2.2353		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.003, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.444E03	**StatLow**	N/A
Max	4.711E03	**NWithinSpec**	50
Mean	4.612E03	**NOutsideSpec**	0
StdDev	64.555	**90%**	4.700E03
25%	4.578E03	**Range**	267.215
Mean+3*StdDev	4.805E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.418E03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.3875		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

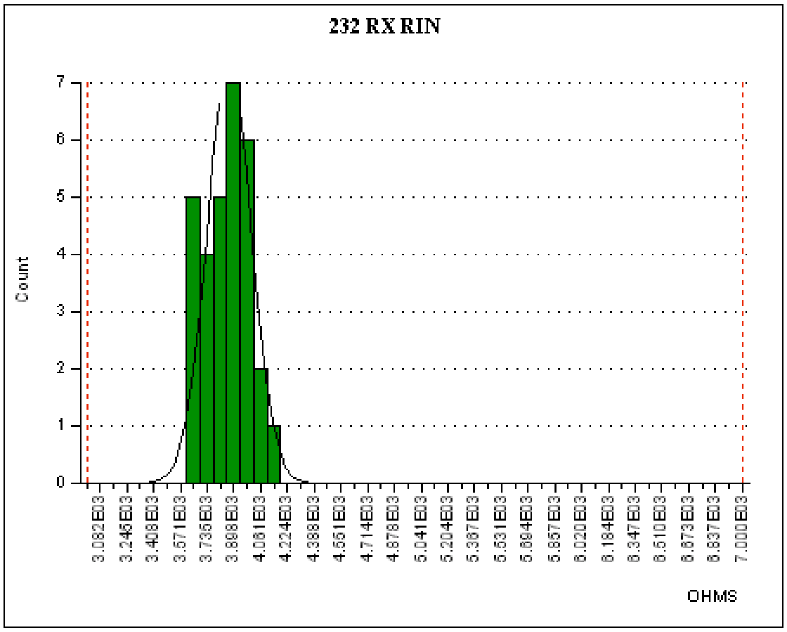
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=4.004, Test.Name=232 RX RIN



Statistics: (OHMS)

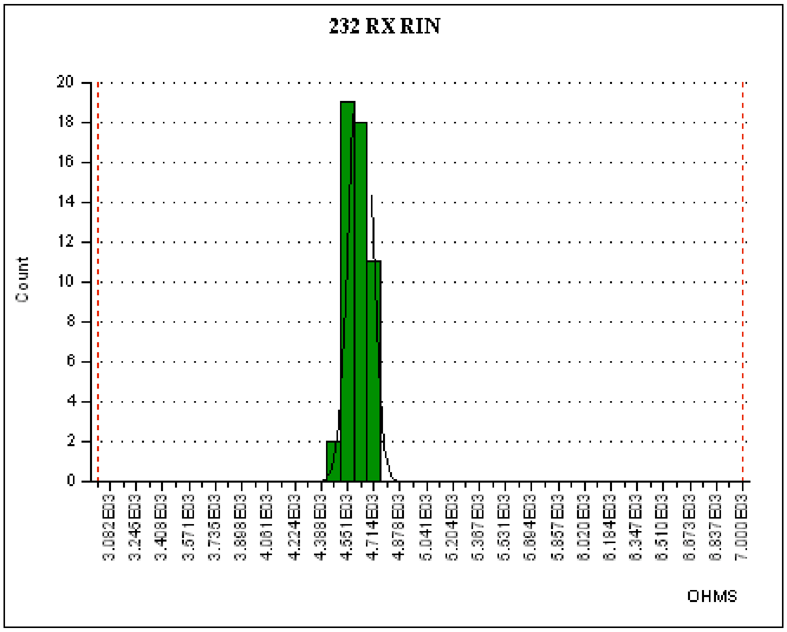
Min	3.631E03	**Skew**	0.0426
Max	4.103E03	**StatHigh**	N/A
Mean	3.857E03	**StatLow**	N/A
StdDev	134.084	**NWithinSpec**	30
25%	3.742E03	**NOutsideSpec**	0
Mean+3*StdDev	4.260E03	**90%**	4.023E03
		Range	472.029
Mean-3*StdDev	3.455E03	**NOutsideSpec**	0
Cpk	2.1315		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=4.004, Test.Name=232 RX RIN



Statistics: (OHMS)

Min	4.453E03	**StatLow**	N/A
Max	4.720E03	**NWithinSpec**	50
Mean	4.612E03	**NOutsideSpec**	0
StdDev	63.000	**90%**	4.691E03
25%	4.577E03	**Range**	266.883
Mean+3*StdDev	4.801E03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	4.423E03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.2708		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

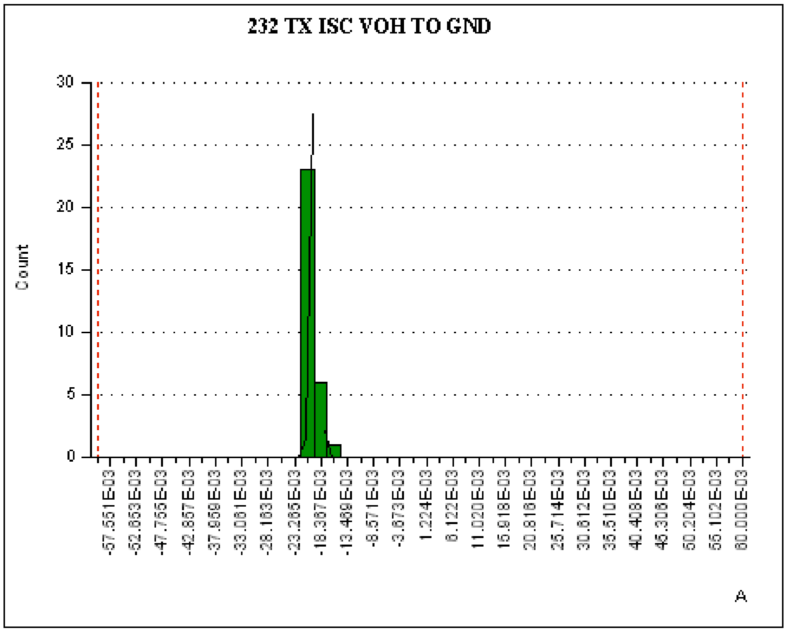
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=6.000, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

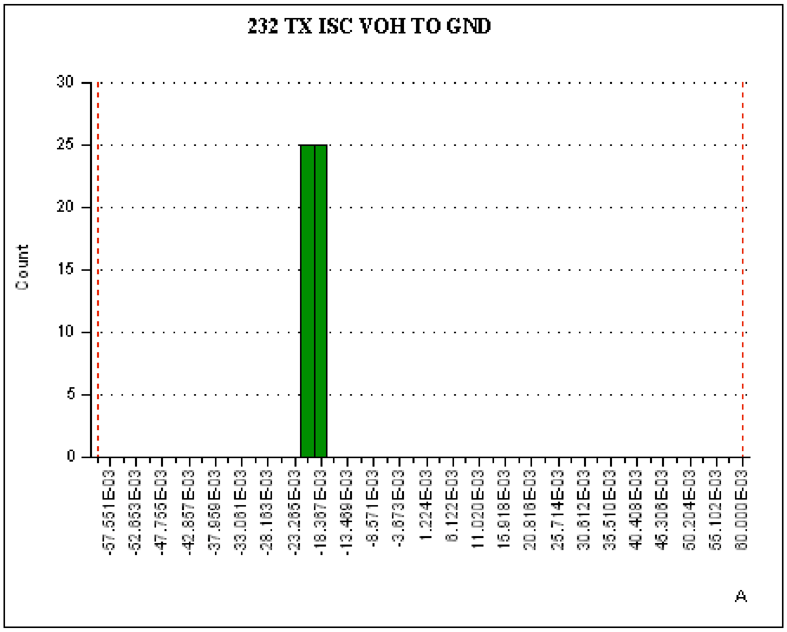
Min	-20.450E-03	**Skew**	2.9917
Max	-16.721E-03	**StatHigh**	N/A
Mean	-19.761E-03	**StatLow**	N/A
StdDev	719.047E-06	**NWithinSpec**	30
25%	-20.116E-03	**NOutsideSpec**	0
Mean+3*StdDev	-17.604E-03	**90%**	-19.159E-03
		Range	3.729E-03
Mean-3*StdDev	-21.918E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.000, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-20.035E-03	**StatLow**	N/A
Max	-19.115E-03	**NWithinSpec**	50
Mean	-19.571E-03	**NOutsideSpec**	0
StdDev	188.733E-06	**90%**	-19.325E-03
25%	-19.700E-03	**Range**	919.577E-06
Mean+3*StdDev	-19.005E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-20.137E-03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.0062		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

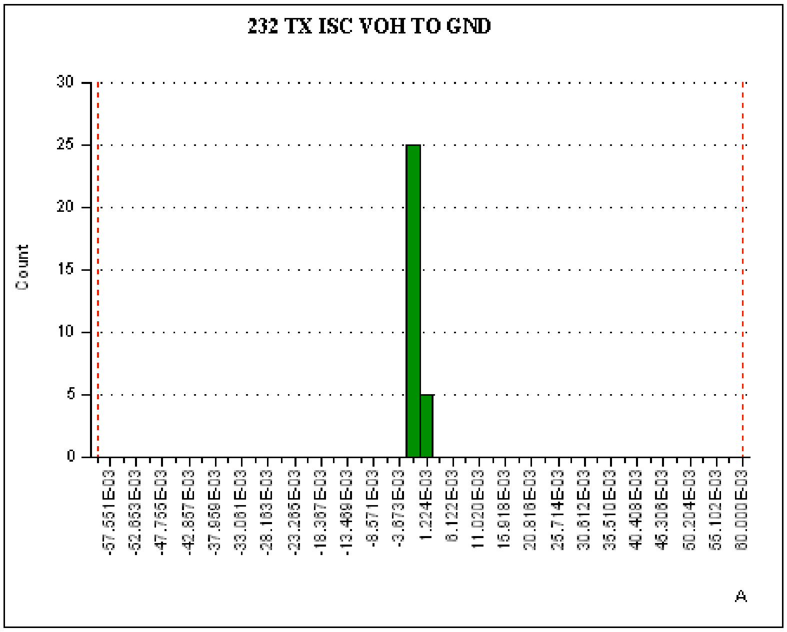
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=6.001, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

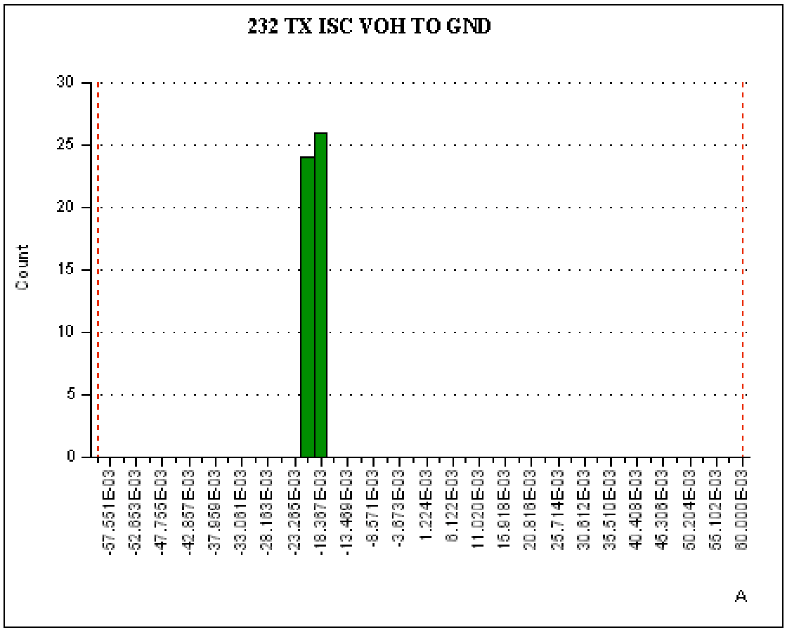
Min	-30.165E-06	**Skew**	-0.6290
Max	3.761E-06	**StatHigh**	N/A
Mean	-8.547E-06	**StatLow**	N/A
StdDev	8.759E-06	**NWithinSpec**	30
25%	-14.104E-06	**NOutsideSpec**	0
Mean+3*StdDev	17.731E-06	**90%**	1.379E-06
		Range	33.926E-06
Mean-3*StdDev	-34.825E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.001, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-20.019E-03	**StatLow**	N/A
Max	-19.113E-03	**NWithinSpec**	50
Mean	-19.573E-03	**NOutsideSpec**	0
StdDev	191.849E-06	**90%**	-19.328E-03
25%	-19.687E-03	**Range**	906.255E-06
Mean+3*StdDev	-18.997E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-20.149E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.0603		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

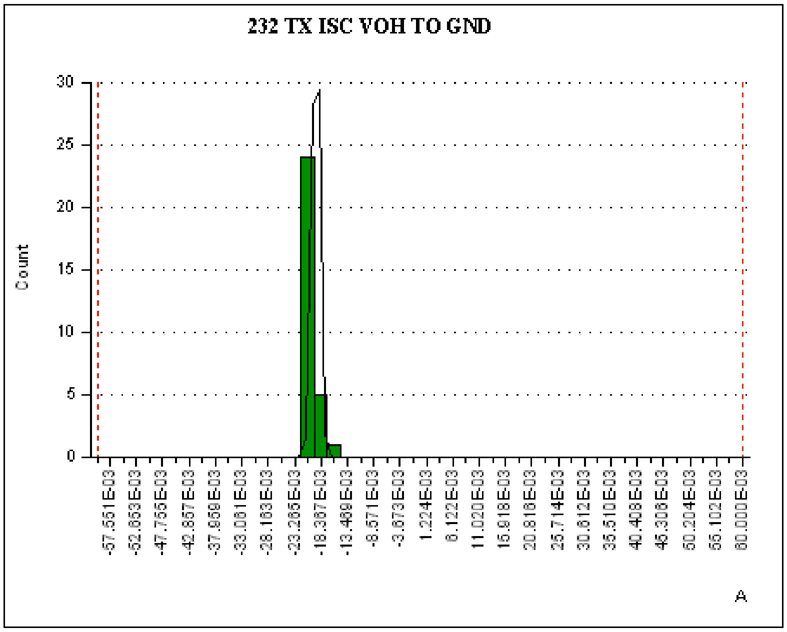
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=6.002, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

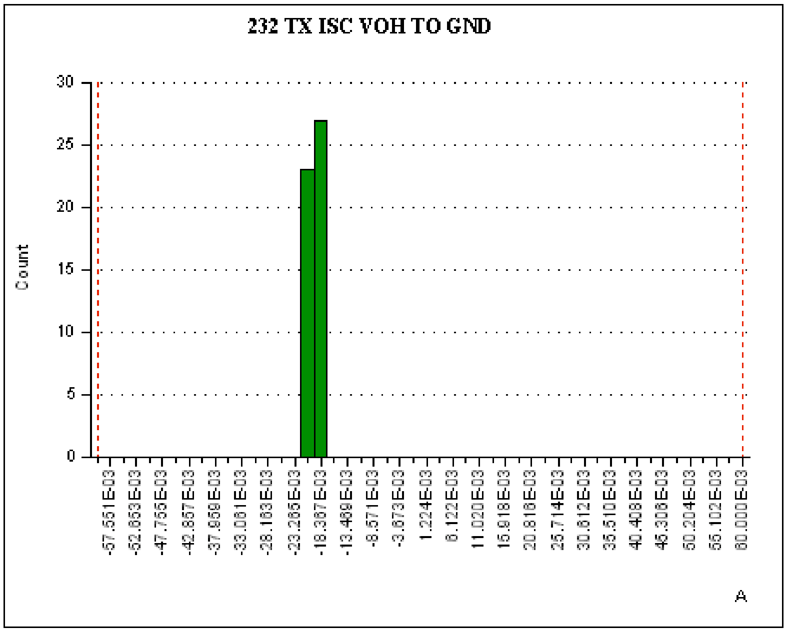
Min	-20.446E-03	**Skew**	3.1448
Max	-16.699E-03	**StatHigh**	N/A
Mean	-19.783E-03	**StatLow**	N/A
StdDev	711.600E-06	**NWithinSpec**	30
25%	-20.161E-03	**NOutsideSpec**	0
Mean+3*StdDev	-17.648E-03	**90%**	-19.224E-03
		Range	3.747E-03
Mean-3*StdDev	-21.917E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.002, Test.Name=232 TX ISC VOH TO GND



Statistics: (A)

Min	-20.026E-03	**StatLow**	N/A
Max	-19.022E-03	**NWithinSpec**	50
Mean	-19.569E-03	**NOutsideSpec**	0
StdDev	194.119E-06	**90%**	-19.341E-03
25%	-19.688E-03	**Range**	1.004E-03
Mean+3*StdDev	-18.986E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-20.151E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.1180		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

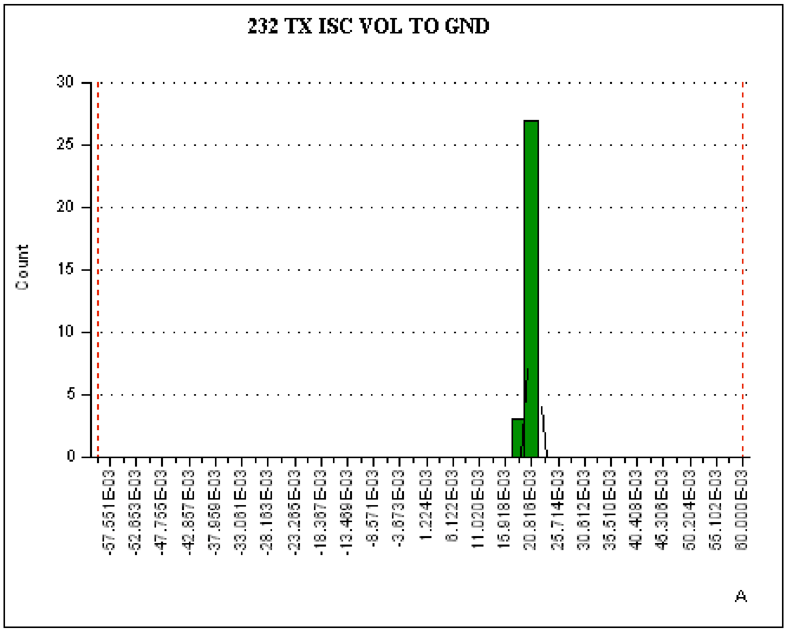
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=6.003, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

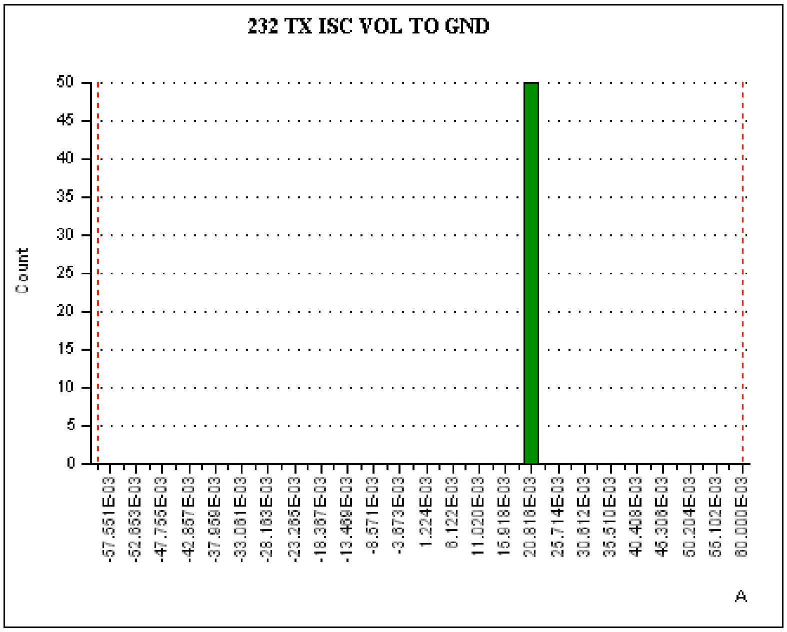
Min	18.326E-03	**Skew**	-1.8981
Max	21.012E-03	**StatHigh**	N/A
Mean	20.324E-03	**StatLow**	N/A
StdDev	564.162E-06	**NWithinSpec**	30
25%	20.141E-03	**NOutsideSpec**	0
Mean+3*StdDev	22.016E-03	**90%**	20.839E-03
		Range	2.686E-03
Mean-3*StdDev	18.631E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.003, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	19.721E-03	**StatLow**	N/A
Max	20.517E-03	**NWithinSpec**	50
Mean	20.092E-03	**NOutsideSpec**	0
StdDev	184.188E-06	**90%**	20.326E-03
25%	19.954E-03	**Range**	796.303E-06
Mean+3*StdDev	20.645E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	19.540E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.2150		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

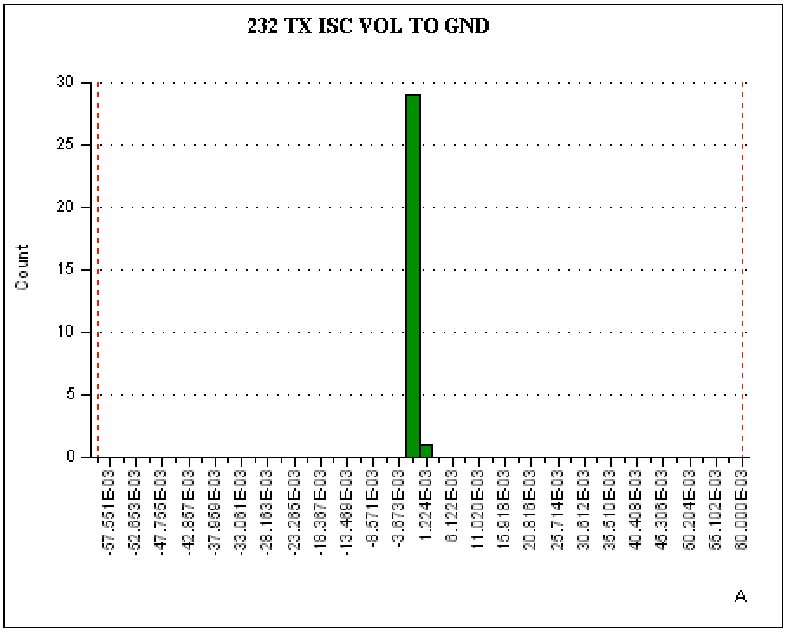
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=6.004, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

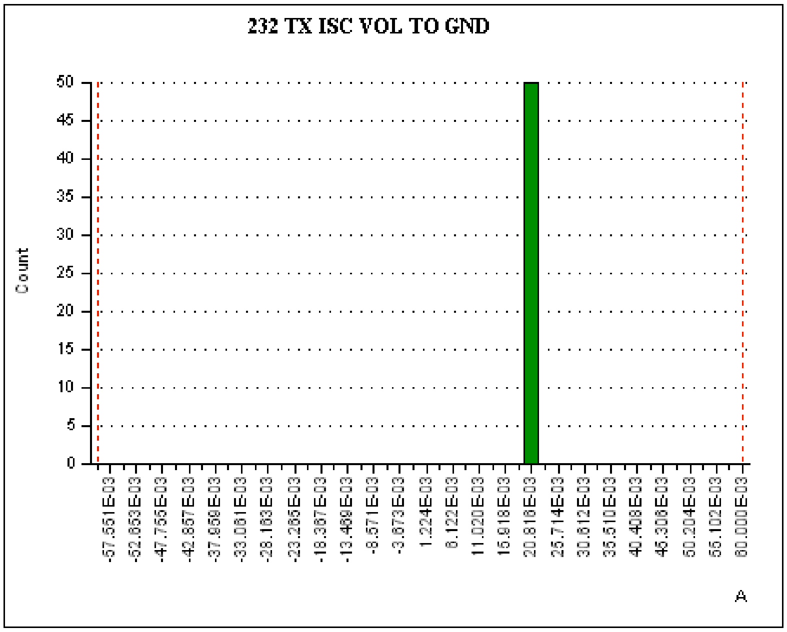
Min	-26.088E-06	**Skew**	-0.5104
Max	2.867E-06	**StatHigh**	N/A
Mean	-9.938E-06	**StatLow**	N/A
StdDev	6.926E-06	**NWithinSpec**	30
25%	-12.020E-06	**NOutsideSpec**	0
Mean+3*StdDev	10.841E-06	**90%**	-1.301E-06
		Range	28.956E-06
Mean-3*StdDev	-30.717E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.004, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	19.740E-03	**StatLow**	N/A
Max	20.555E-03	**NWithinSpec**	50
Mean	20.107E-03	**NOutsideSpec**	0
StdDev	182.327E-06	**90%**	20.334E-03
25%	19.968E-03	**Range**	815.254E-06
Mean+3*StdDev	20.654E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	19.560E-03	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.2675		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

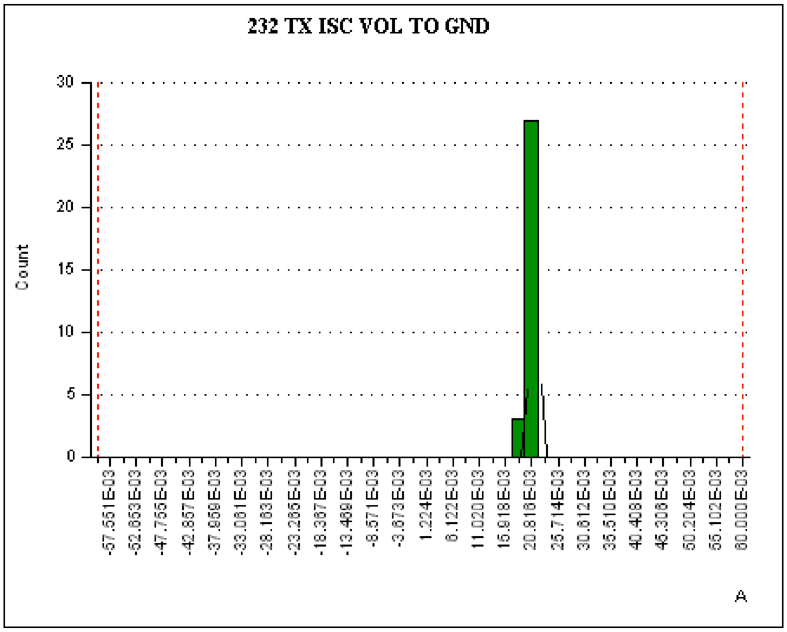
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=6.005, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

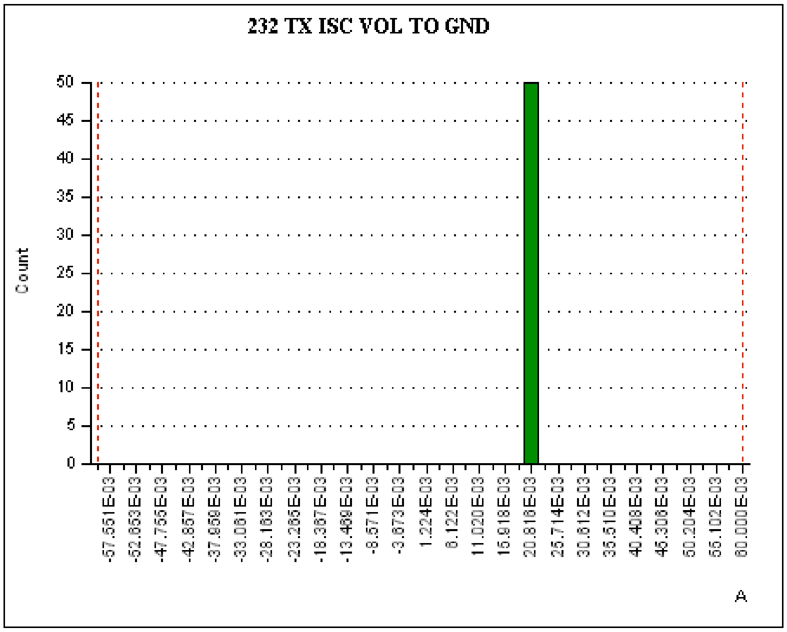
Min	18.371E-03	**Skew**	-1.9905
Max	21.081E-03	**StatHigh**	N/A
Mean	20.410E-03	**StatLow**	N/A
StdDev	568.813E-06	**NWithinSpec**	30
25%	20.206E-03	**NOutsideSpec**	0
Mean+3*StdDev	22.116E-03	**90%**	20.930E-03
		Range	2.711E-03
Mean-3*StdDev	18.703E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=6.005, Test.Name=232 TX ISC VOL TO GND



Statistics: (A)

Min	19.787E-03	**StatLow**	N/A
Max	20.609E-03	**NWithinSpec**	50
Mean	20.156E-03	**NOutsideSpec**	0
StdDev	186.416E-06	**90%**	20.386E-03
25%	20.030E-03	**Range**	822.201E-06
Mean+3*StdDev	20.715E-03	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	19.596E-03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.3036		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

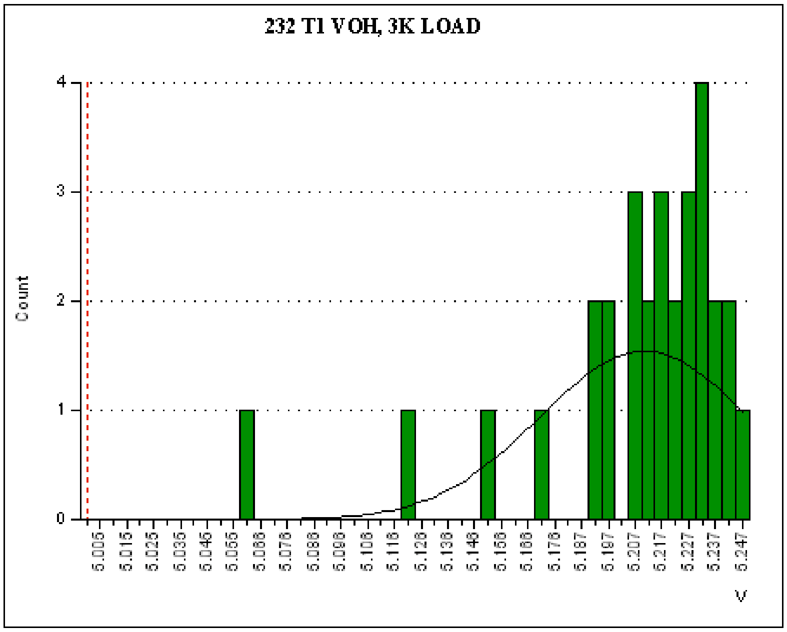
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=7.000, Test.Name=232 T1 VOH, 3K LOAD



Statistics: (V)

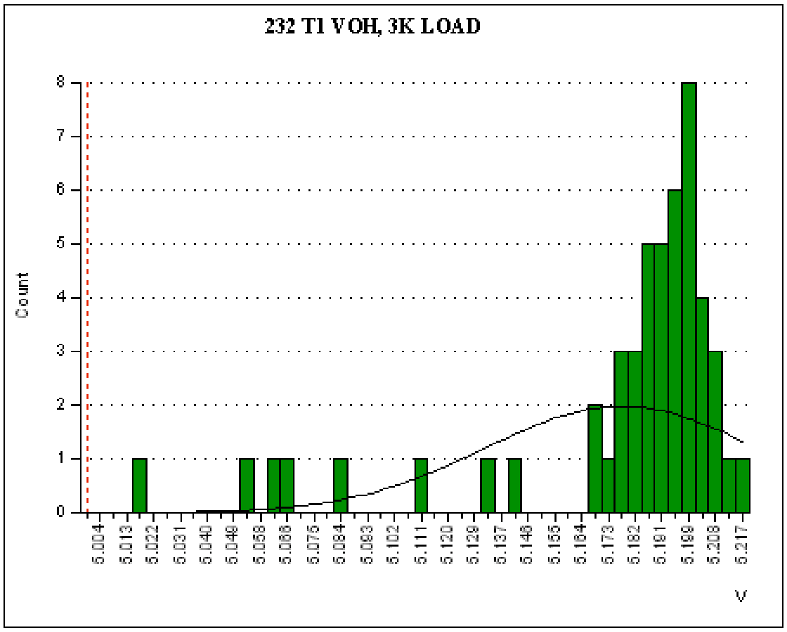
Min	5.059	**Skew**	-2.3883
Max	5.247	**StatHigh**	N/A
Mean	5.208	**StatLow**	N/A
StdDev	39.081E-03	**NWithinSpec**	30
25%	5.196	**NOutsideSpec**	0
Mean+3*StdDev	5.325	**90%**	5.240
		Range	187.809E-03
Mean-3*StdDev	5.090	**NOutsideSpec**	0
Cpk	1.7717		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.000, Test.Name=232 T1 VOH, 3K LOAD



Statistics: (V)

Min	5.017	**StatLow**	N/A
Max	5.217	**NWithinSpec**	50
Mean	5.175	**NOutsideSpec**	0
StdDev	44.693E-03	**90%**	5.205
25%	5.178	**Range**	199.840E-03
Mean+3*StdDev	5.309	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	5.041	**Cpl**	1.3074
		Cpu	N/A
Cpk	1.3074		
Skew	-2.1676		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

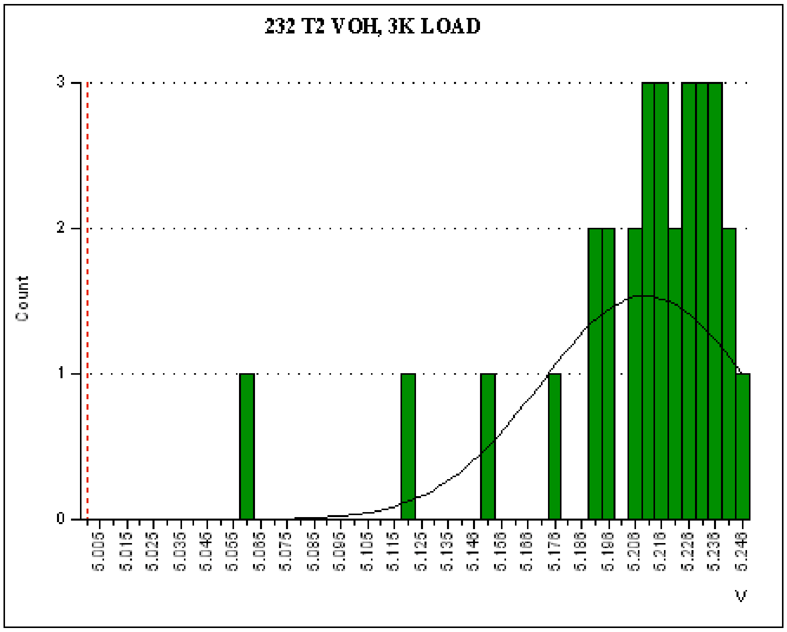
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=7.001, Test.Name=232 T2 VOH, 3K LOAD



Statistics: (V)

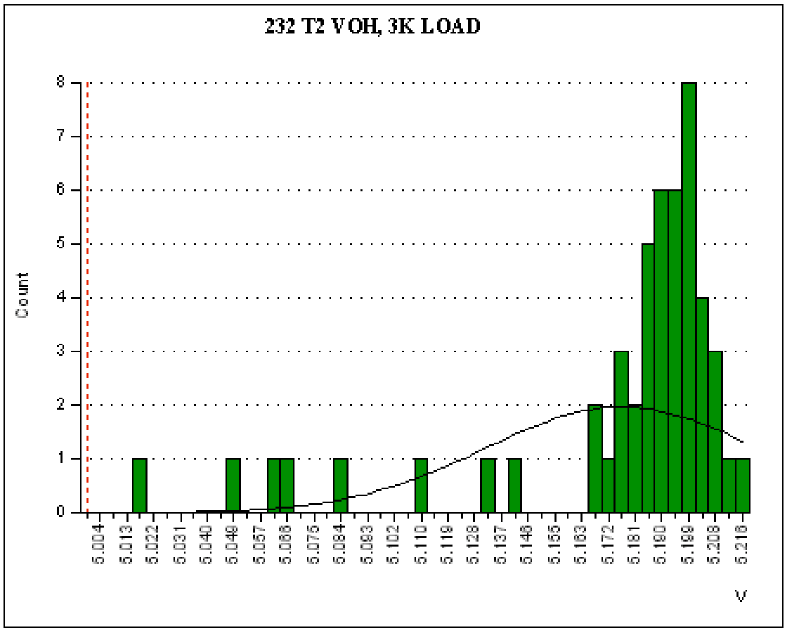
Min	5.059	**Skew**	-2.4017
Max	5.246	**StatHigh**	N/A
Mean	5.207	**StatLow**	N/A
StdDev	39.090E-03	**NWithinSpec**	30
25%	5.196	**NOutsideSpec**	0
Mean+3*StdDev	5.325	**90%**	5.239
		Range	187.202E-03
Mean-3*StdDev	5.090	**NOutsideSpec**	0
Cpk	1.7675		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.001, Test.Name=232 T2 VOH, 3K LOAD



Statistics: (V)

Min	5.017	**StatLow**	N/A
Max	5.216	**NWithinSpec**	50
Mean	5.175	**NOutsideSpec**	0
StdDev	44.708E-03	**90%**	5.205
25%	5.177	**Range**	199.404E-03
Mean+3*StdDev	5.309	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	5.041	**Cpl**	1.3033
		Cpu	N/A
Cpk	1.3033		
Skew	-2.1642		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

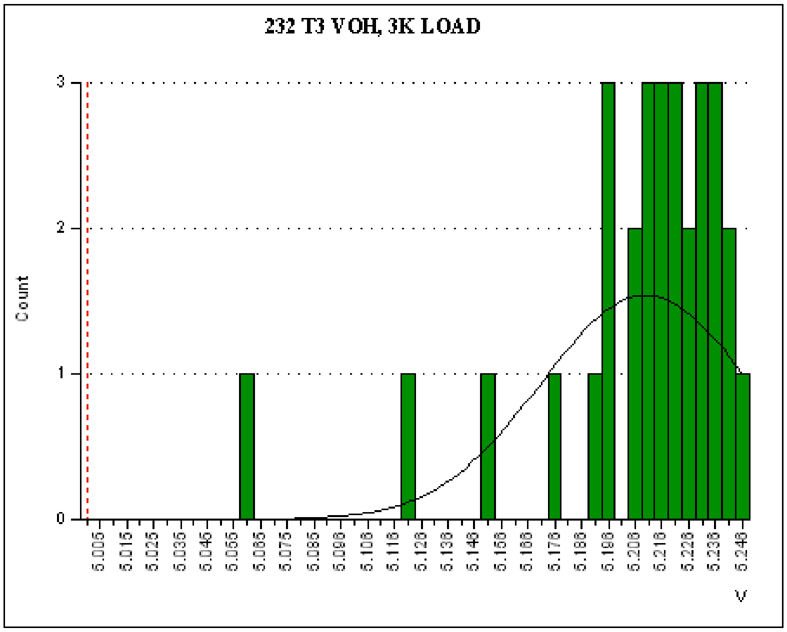
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=7.002, Test.Name=232 T3 VOH, 3K LOAD



Statistics: (V)

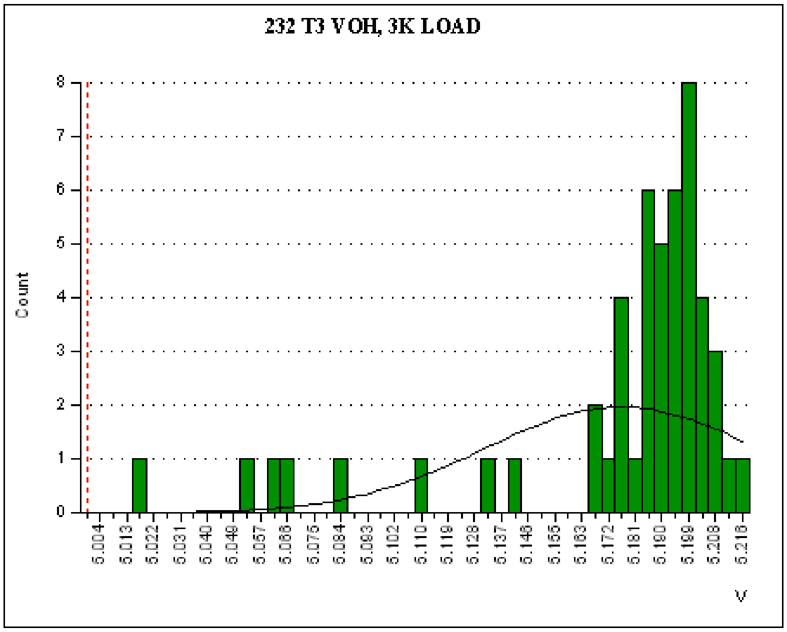
Min	5.060	**Skew**	-2.4083
Max	5.246	**StatHigh**	N/A
Mean	5.208	**StatLow**	N/A
StdDev	39.056E-03	**NWithinSpec**	30
25%	5.195	**NOutsideSpec**	0
Mean+3*StdDev	5.325	**90%**	5.239
		Range	186.914E-03
Mean-3*StdDev	5.091	**NOutsideSpec**	0
Cpk	1.7728		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.002, Test.Name=232 T3 VOH, 3K LOAD



Statistics: (V)

Min	5.017	**StatLow**	N/A
Max	5.216	**NWithinSpec**	50
Mean	5.175	**NOutsideSpec**	0
StdDev	44.742E-03	**90%**	5.205
25%	5.177	**Range**	199.374E-03
Mean+3*StdDev	5.309	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	5.041	**Cpl**	1.3031
Cpk	1.3031	**Cpu**	N/A
Skew	-2.1651		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

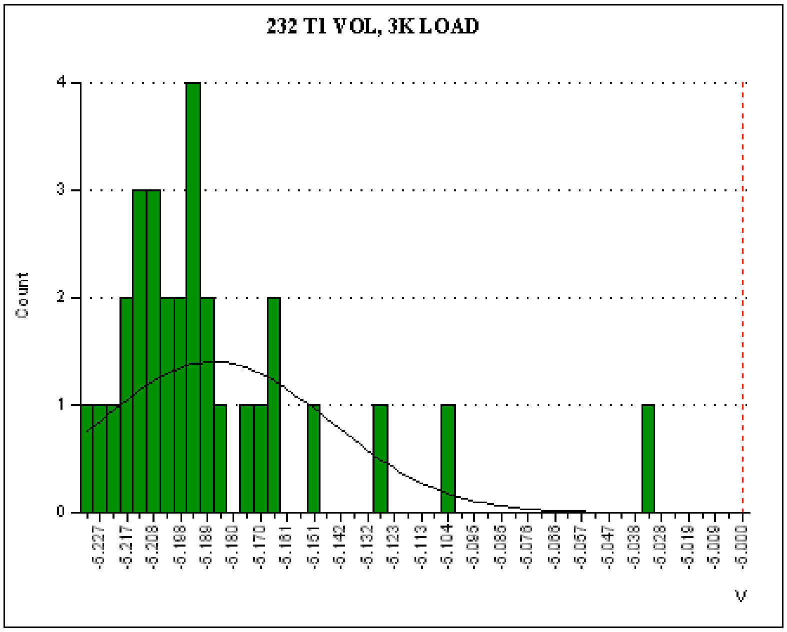
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=7.003, Test.Name=232 T1 VOL, 3K LOAD



Statistics: (V)

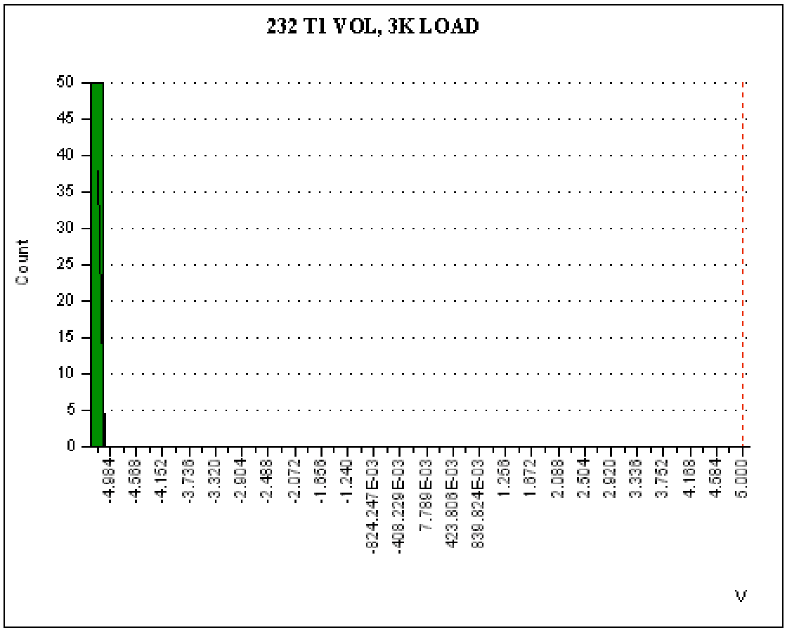
Min	-5.232	**Skew**	2.2959
Max	-5.034	**StatHigh**	N/A
Mean	-5.187	**StatLow**	N/A
StdDev	40.226E-03	**NWithinSpec**	30
25%	-5.211	**NOutsideSpec**	0
Mean+3*StdDev	-5.066	**90%**	-5.140
		Range	197.126E-03
Mean-3*StdDev	-5.308	**NOutsideSpec**	0
Cpk	1.5505		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.003, Test.Name=232 T1 VOL, 3K LOAD



Statistics: (V)

Min	-5.192	**StatLow**	N/A
Max	-5.138	**NWithinSpec**	50
Mean	-5.166	**NOutsideSpec**	0
StdDev	12.877E-03	**90%**	-5.148
25%	-5.175	**Range**	54.659E-03
Mean+3*StdDev	-5.127	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-5.204	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.1908		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

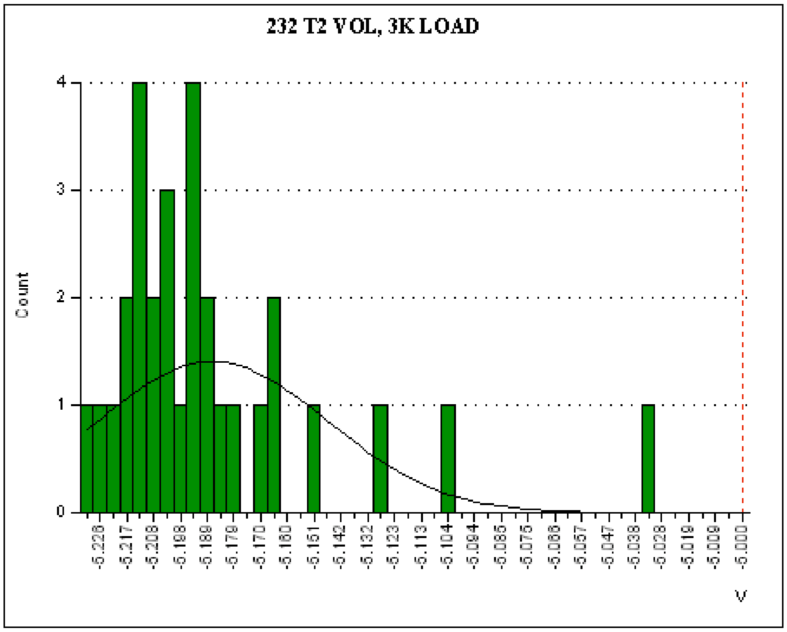
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=7.004, Test.Name=232 T2 VOL, 3K LOAD



Statistics: (V)

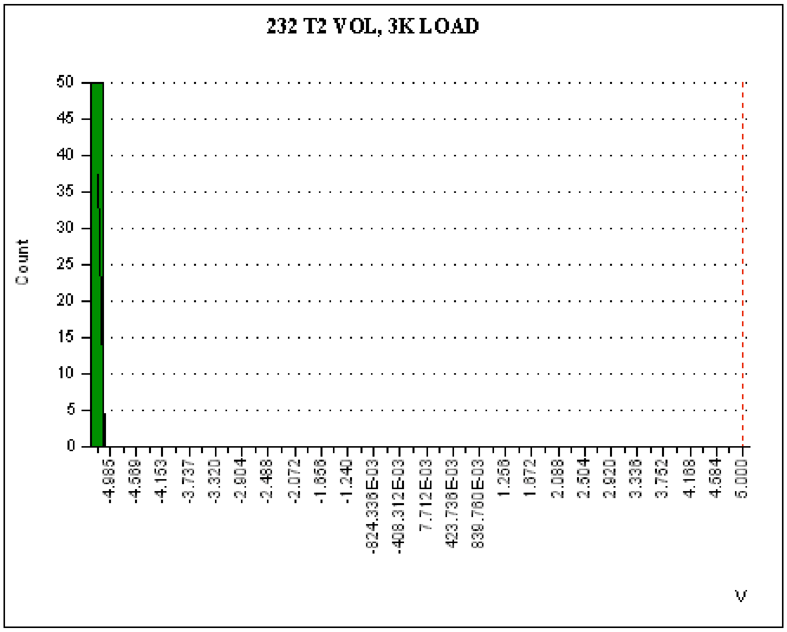
Min	-5.231	**Skew**	2.3006
Max	-5.035	**StatHigh**	N/A
Mean	-5.187	**StatLow**	N/A
StdDev	40.197E-03	**NWithinSpec**	30
25%	-5.213	**NOutsideSpec**	0
Mean+3*StdDev	-5.067	**90%**	-5.141
		Range	196.285E-03
Mean-3*StdDev	-5.308	**NOutsideSpec**	0
Cpk	1.5539		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.004, Test.Name=232 T2 VOL, 3K LOAD



Statistics: (V)

Min	-5.193	**StatLow**	N/A
Max	-5.138	**NWithinSpec**	50
Mean	-5.166	**NOutsideSpec**	0
StdDev	12.925E-03	**90%**	-5.148
25%	-5.175	**Range**	55.078E-03
Mean+3*StdDev	-5.127	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-5.205	**Cpl**	N/A
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.2002		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

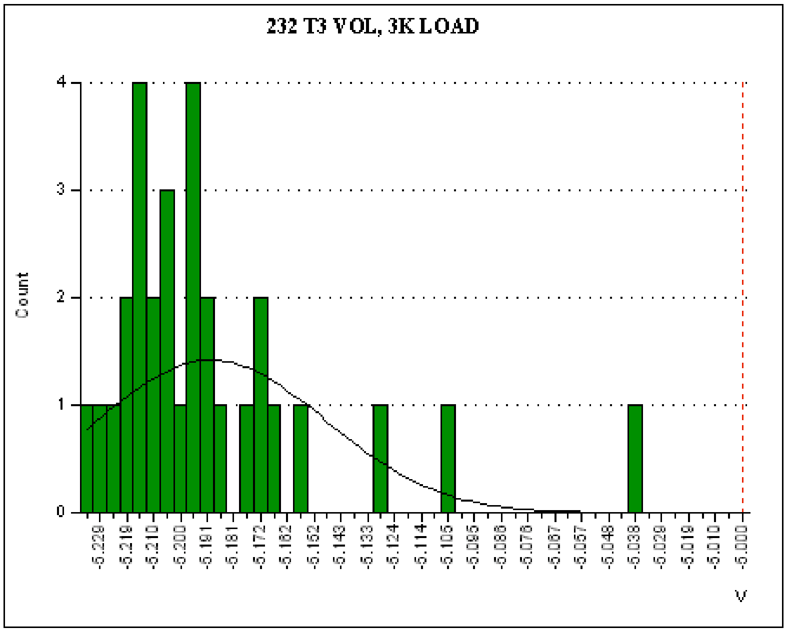
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=7.005, Test.Name=232 T3 VOL, 3K LOAD



Statistics: (V)

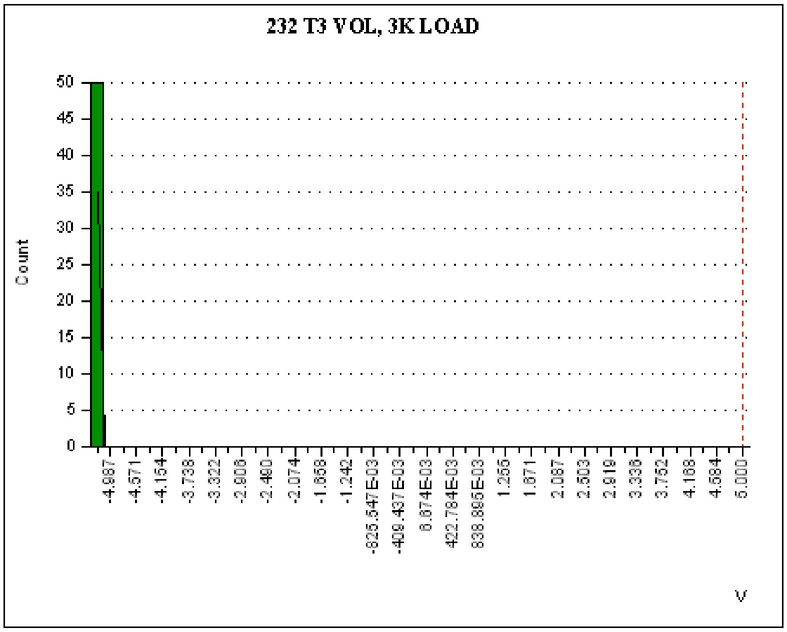
Min	-5.233	**Skew**	2.3197
Max	-5.037	**StatHigh**	N/A
Mean	-5.190	**StatLow**	N/A
StdDev	40.152E-03	**NWithinSpec**	30
25%	-5.215	**NOutsideSpec**	0
Mean+3*StdDev	-5.069	**90%**	-5.144
		Range	196.419E-03
Mean-3*StdDev	-5.310	**NOutsideSpec**	0
Cpk	1.5738		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=7.005, Test.Name=232 T3 VOL, 3K LOAD



Statistics: (V)

Min	-5.195	**StatLow**	N/A
Max	-5.140	**NWithinSpec**	50
Mean	-5.168	**NOutsideSpec**	0
StdDev	12.882E-03	**90%**	-5.150
25%	-5.177	**Range**	54.808E-03
Mean+3*StdDev	-5.129	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	-5.206	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.1661		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

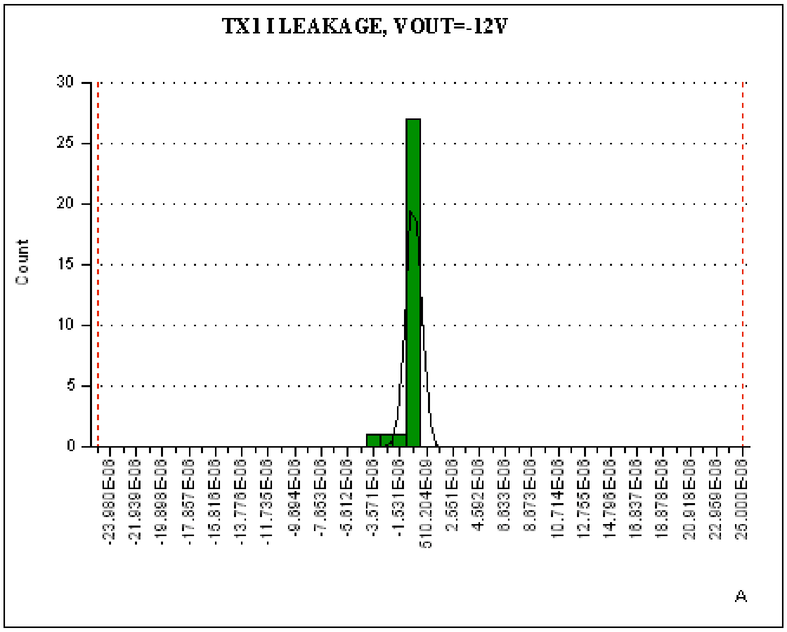
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=8.000, Test.Name=TX1 I LEAKAGE, VOUT=-12V



Statistics: (A)

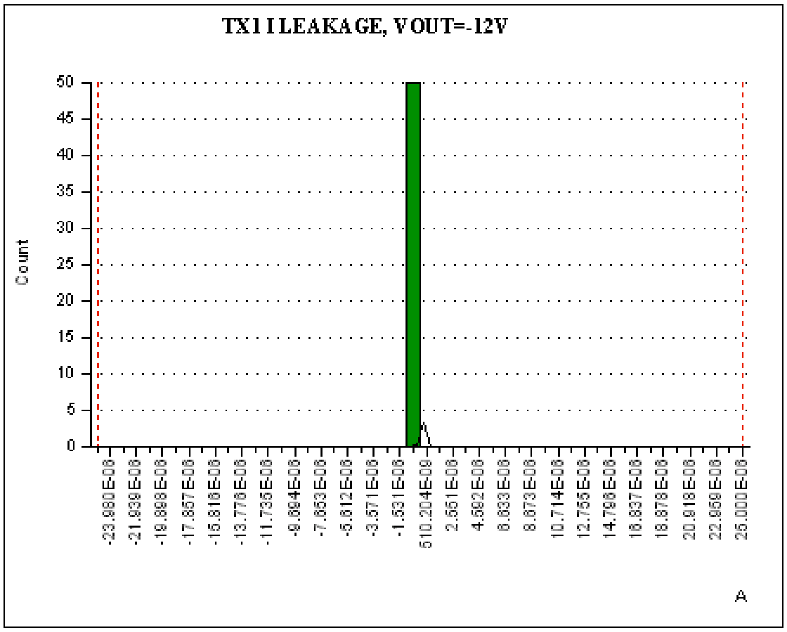
Min	-3.391E-06	**Skew**	-3.6936
Max	-306.514E-09	**StatHigh**	N/A
Mean	-777.907E-09	**StatLow**	N/A
StdDev	587.244E-09	**NWithinSpec**	30
25%	-728.169E-09	**NOutsideSpec**	0
Mean+3*StdDev	983.823E-09	**90%**	-509.436E-09
		Range	3.085E-06
Mean-3*StdDev	-2.540E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.000, Test.Name=TX1 I LEAKAGE, VOUT=-12V



Statistics: (A)

Min	-401.145E-09	**StatLow**	N/A
Max	-75.459E-09	**NWithinSpec**	50
Mean	-218.183E-09	**NOutsideSpec**	0
StdDev	73.485E-09	**90%**	-136.885E-09
25%	-270.238E-09	**Range**	325.686E-09
Mean+3*StdDev	2.272E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-438.638E-09	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.3674		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

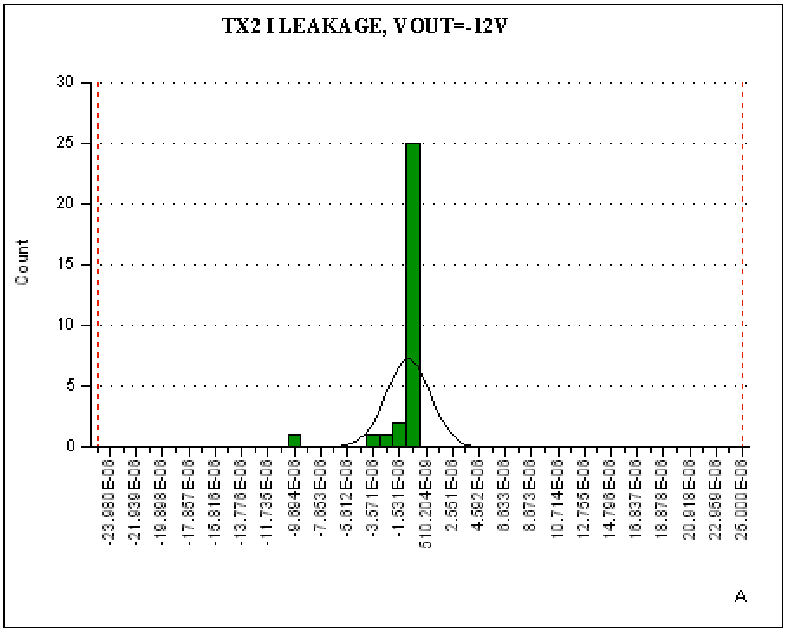
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=8.001, Test.Name=TX2 I LEAKAGE, VOUT=-12V



Statistics: (A)

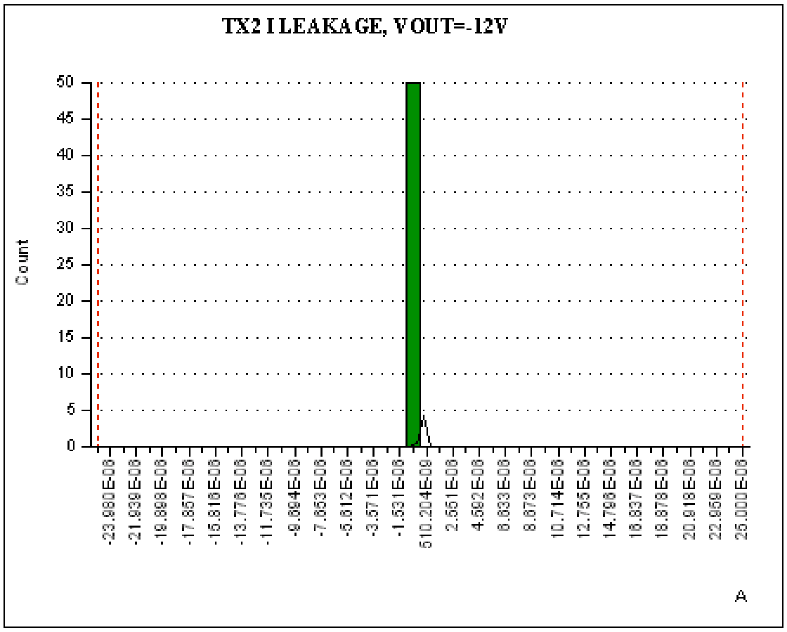
Min	-9.335E-06	**Skew**	-4.3537
Max	-435.059E-09	**StatHigh**	N/A
Mean	-1.149E-06	**StatLow**	N/A
StdDev	1.684E-06	**NWithinSpec**	30
25%	-816.938E-09	**NOutsideSpec**	0
Mean+3*StdDev	3.903E-06	**90%**	-469.669E-09
		Range	8.900E-06
Mean-3*StdDev	-6.202E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.001, Test.Name=TX2 I LEAKAGE, VOUT=-12V



Statistics: (A)

Min	-518.898E-09	**StatLow**	N/A
Max	-63.496E-09	**NWithinSpec**	50
Mean	-221.826E-09	**NOutsideSpec**	0
StdDev	77.101E-09	**90%**	-139.447E-09
25%	-263.888E-09	**Range**	455.402E-09
Mean+3*StdDev	9.478E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-453.130E-09	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-1.1872		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

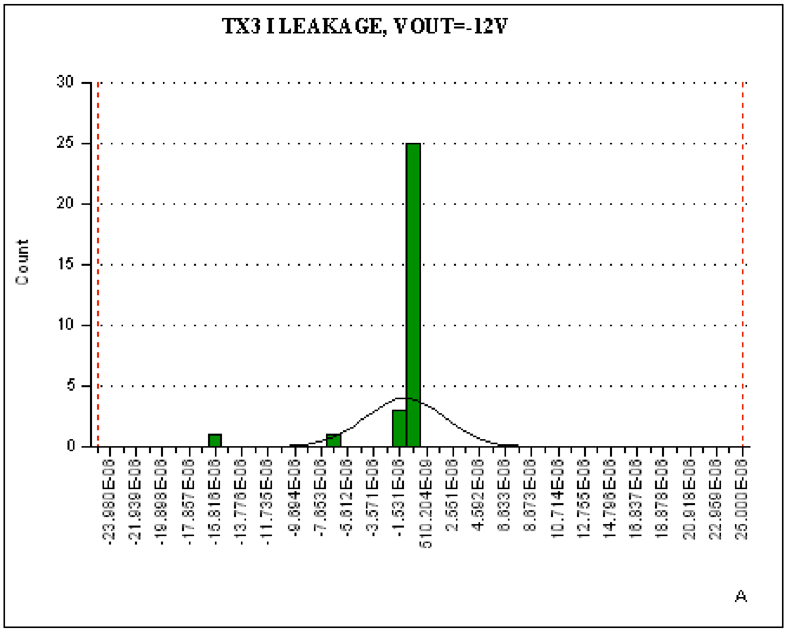
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=8.002, Test.Name=TX3 I LEAKAGE, VOUT=-12V



Statistics: (A)

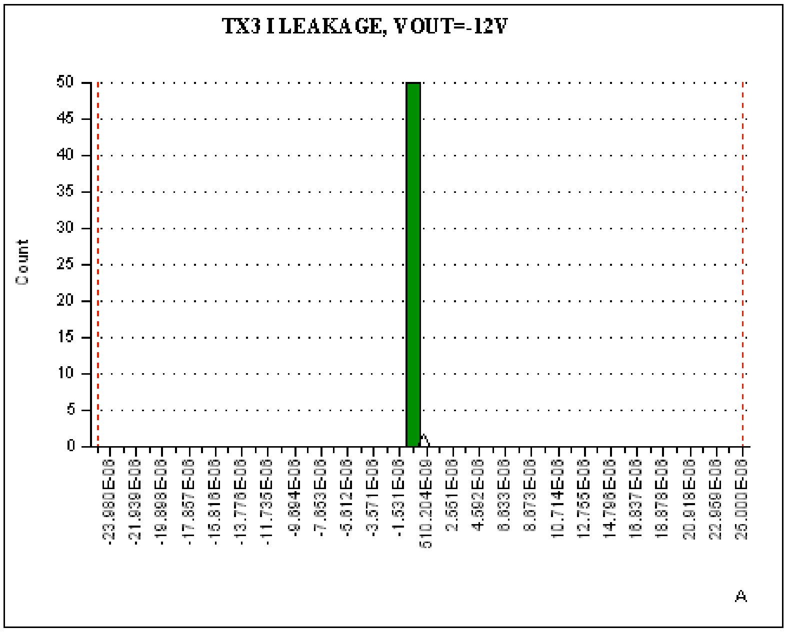
Min	-16.267E-06	**Skew**	-4.5212
Max	-366.020E-09	**StatHigh**	N/A
Mean	-1.391E-06	**StatLow**	N/A
StdDev	3.045E-06	**NWithinSpec**	30
25%	-757.237E-09	**NOutsideSpec**	0
Mean+3*StdDev	7.744E-06	**90%**	-475.217E-09
		Range	15.901E-06
Mean-3*StdDev	-10.525E-06	**NOutsideSpec**	0
Cpk	2.5846		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.002, Test.Name=TX3 I LEAKAGE, VOUT=-12V



Statistics: (A)

Min	-373.800E-09	**StatLow**	N/A
Max	-103.194E-09	**NWithinSpec**	50
Mean	-205.019E-09	**NOutsideSpec**	0
StdDev	62.797E-09	**90%**	-140.105E-09
25%	-236.739E-09	**Range**	270.606E-09
Mean+3*StdDev	-16.627E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-393.410E-09	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.9578		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

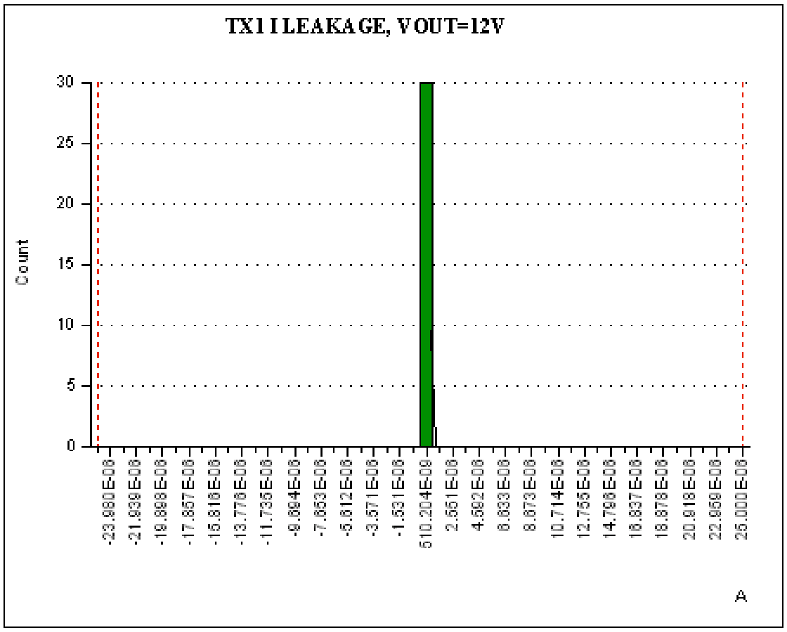
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=8.003, Test.Name=TX1 I LEAKAGE, VOUT=12V



Statistics: (A)

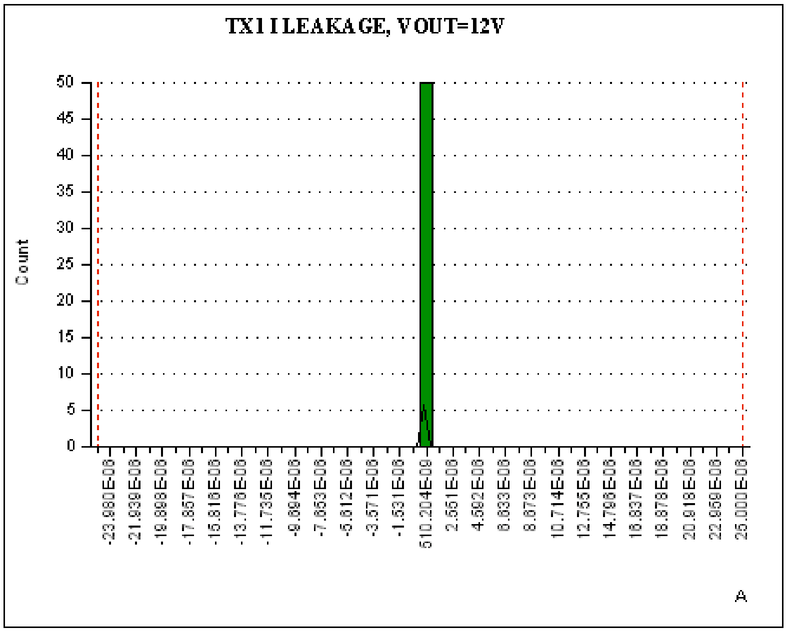
Min	42.295E-09	**Skew**	1.3856
Max	515.006E-09	**StatHigh**	N/A
Mean	185.926E-09	**StatLow**	N/A
StdDev	152.285E-09	**NWithinSpec**	30
25%	100.228E-09	**NOutsideSpec**	0
Mean+3*StdDev	642.781E-09	**90%**	470.231E-09
		Range	472.711E-09
Mean-3*StdDev	-270.929E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.003, Test.Name=TX1 I LEAKAGE, VOUT=12V



Statistics: (A)

Min	22.348E-09	**StatLow**	N/A
Max	185.093E-09	**NWithinSpec**	50
Mean	75.650E-09	**NOutsideSpec**	0
StdDev	23.904E-09	**90%**	94.342E-09
25%	64.924E-09	**Range**	162.745E-09
Mean+3*StdDev	147.361E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	3.939E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	1.8003		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

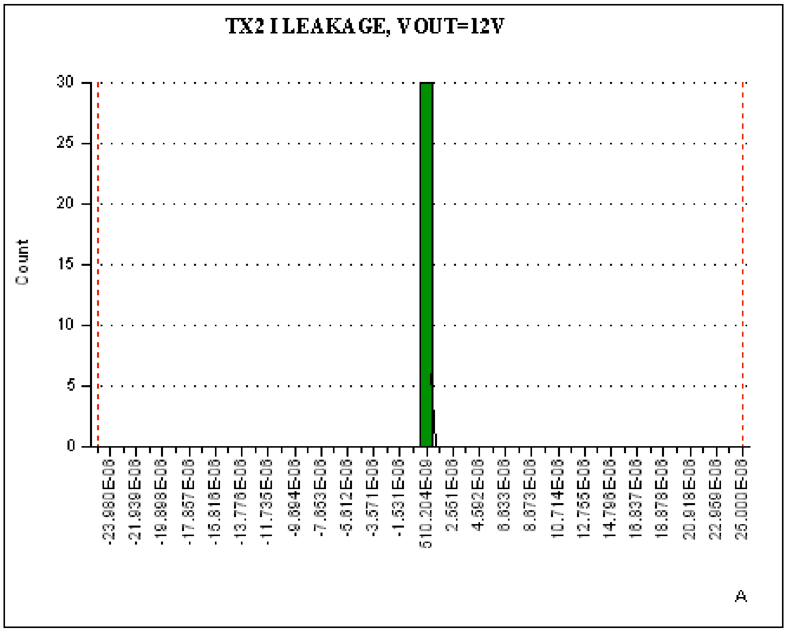
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=8.004, Test.Name=TX2 I LEAKAGE, VOUT=12V



Statistics: (A)

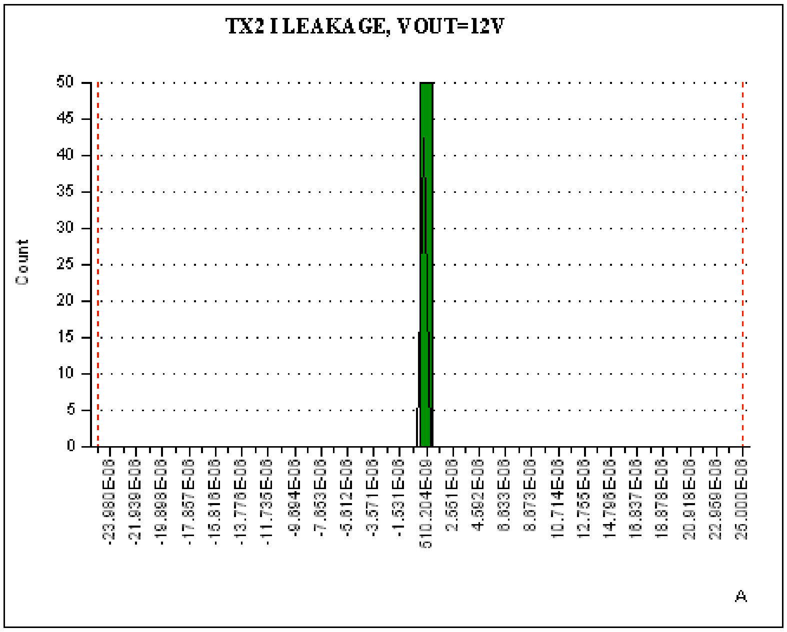
Min	58.007E-09	**Skew**	1.3877
Max	514.121E-09	**StatHigh**	N/A
Mean	172.249E-09	**StatLow**	N/A
StdDev	142.207E-09	**NWithinSpec**	30
25%	85.203E-09	**NOutsideSpec**	0
Mean+3*StdDev	598.871E-09	**90%**	422.948E-09
		Range	456.114E-09
Mean-3*StdDev	-254.373E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.004, Test.Name=TX2 I LEAKAGE, VOUT=12V



Statistics: (A)

Min	37.775E-09	**StatLow**	N/A
Max	262.731E-09	**NWithinSpec**	50
Mean	80.761E-09	**NOutsideSpec**	0
StdDev	35.369E-09	**90%**	119.516E-09
25%	58.529E-09	**Range**	224.957E-09
Mean+3*StdDev	186.867E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-25.345E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	2.9075		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

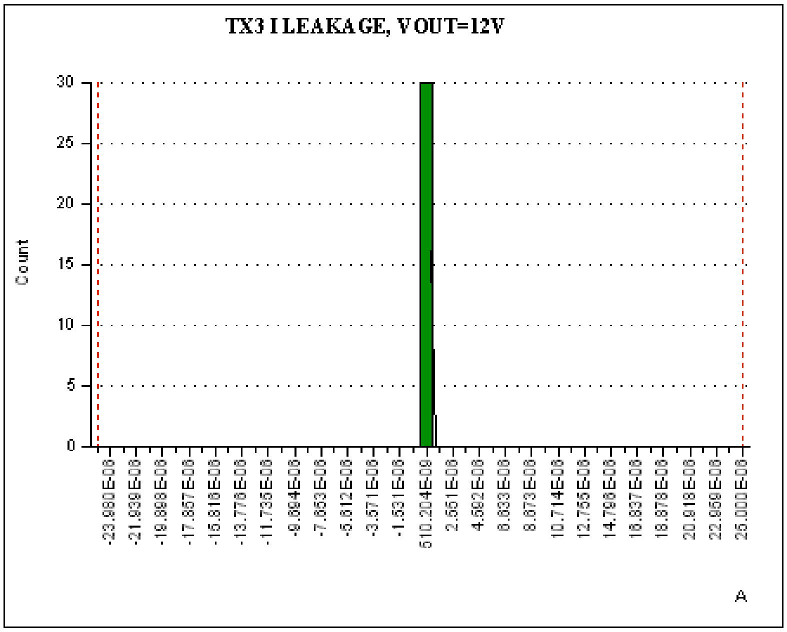
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=8.005, Test.Name=TX3 I LEAKAGE, VOUT=12V



Statistics: (A)

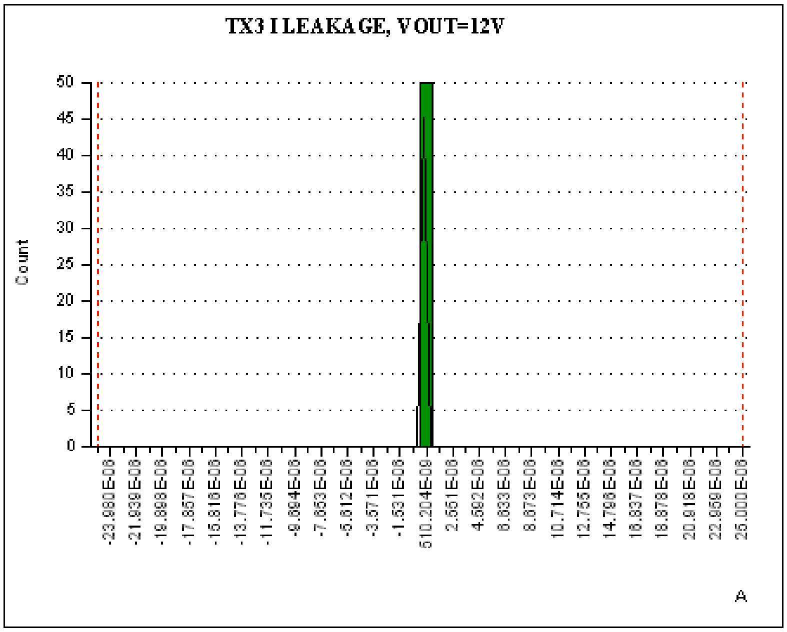
Min	73.131E-09	**Skew**	1.4271
Max	582.757E-09	**StatHigh**	N/A
Mean	211.980E-09	**StatLow**	N/A
StdDev	164.771E-09	**NWithinSpec**	30
25%	117.414E-09	**NOutsideSpec**	0
Mean+3*StdDev	706.294E-09	**90%**	521.244E-09
		Range	509.626E-09
Mean-3*StdDev	-282.334E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=8.005, Test.Name=TX3 I LEAKAGE, VOUT=12V



Statistics: (A)

Min	41.877E-09	**StatLow**	N/A
Max	278.309E-09	**NWithinSpec**	50
Mean	74.061E-09	**NOutsideSpec**	0
StdDev	32.246E-09	**90%**	89.067E-09
25%	59.995E-09	**Range**	236.431E-09
Mean+3*StdDev	170.799E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-22.677E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	5.3402		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

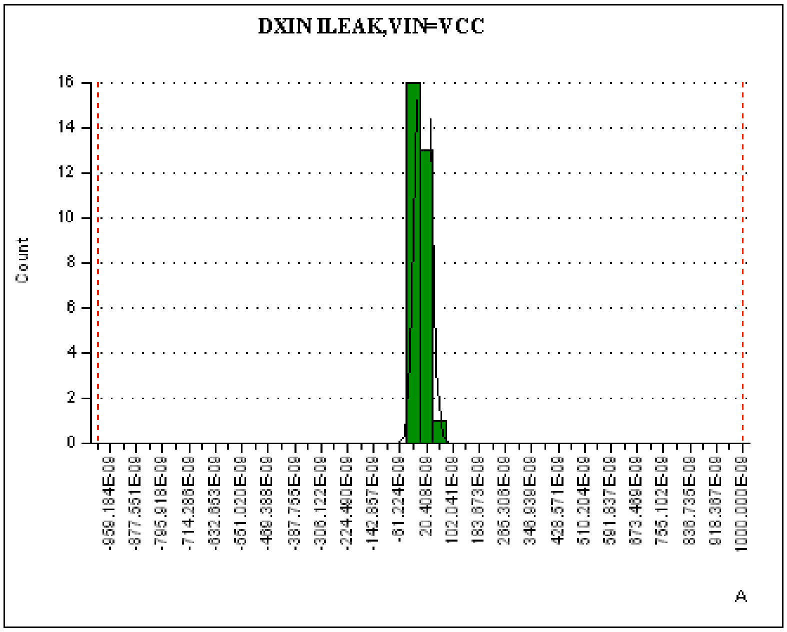
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=9.000, Test.Name=DXIN ILEAK,VIN=VCC



Statistics: (A)

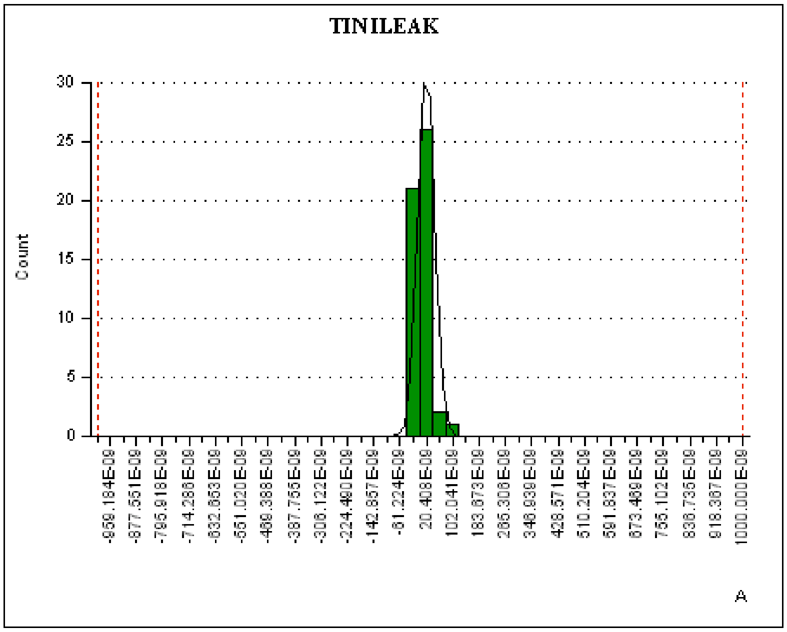
Min	-29.299E-09	**Skew**	0.5393
Max	45.639E-09	**StatHigh**	N/A
Mean	-636.891E-12	**StatLow**	N/A
StdDev	20.301E-09	**NWithinSpec**	30
25%	-17.840E-09	**NOutsideSpec**	0
Mean+3*StdDev	60.265E-09	**90%**	27.936E-09
		Range	74.938E-09
Mean-3*StdDev	-61.539E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=9.000, Test.Name=TIN ILEAK



Statistics: (A)

Min	-26.962E-09	**StatLow**	N/A
Max	101.343E-09	**NWithinSpec**	50
Mean	8.638E-09	**NOutsideSpec**	0
StdDev	25.787E-09	**90%**	38.912E-09
25%	-11.983E-09	**Range**	128.304E-09
Mean+3*StdDev	85.999E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-68.723E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.9498		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

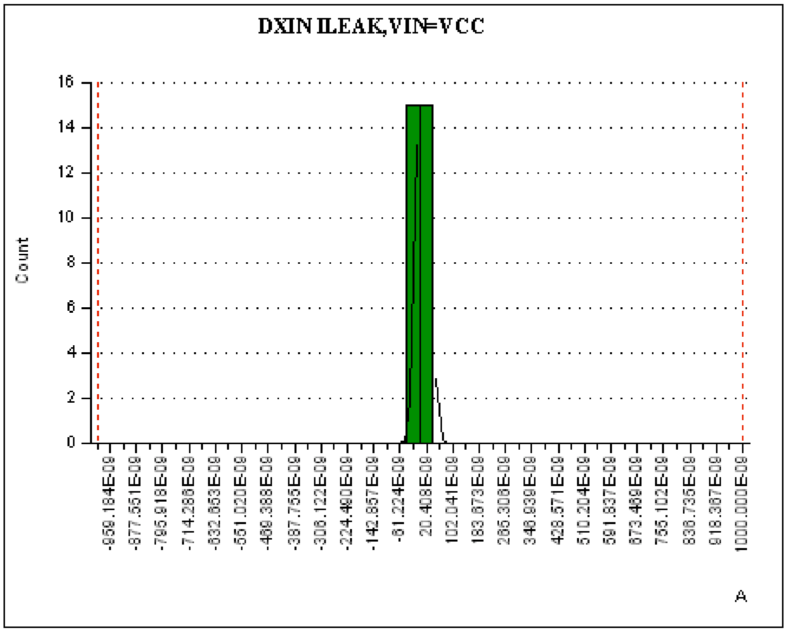
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=9.001, Test.Name=DXIN ILEAK,VIN=VCC



Statistics: (A)

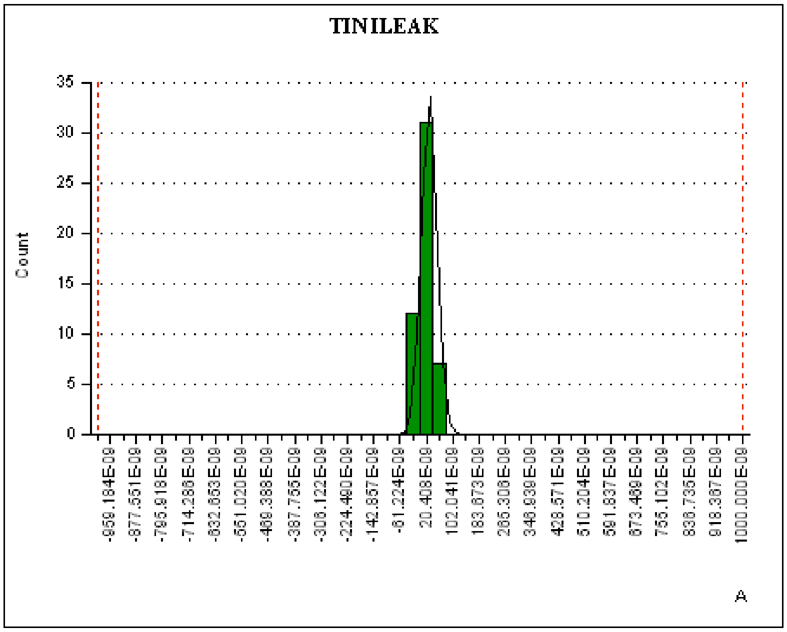
Min	-23.590E-09	**Skew**	0.3592
Max	38.494E-09	**StatHigh**	N/A
Mean	1.585E-09	**StatLow**	N/A
StdDev	18.091E-09	**NWithinSpec**	30
25%	-15.446E-09	**NOutsideSpec**	0
Mean+3*StdDev	55.858E-09	**90%**	25.543E-09
		Range	62.084E-09
Mean-3*StdDev	-52.688E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=9.001, Test.Name=TIN ILEAK



Statistics: (A)

Min	-25.863E-09	**StatLow**	N/A
Max	66.558E-09	**NWithinSpec**	50
Mean	17.844E-09	**NOutsideSpec**	0
StdDev	24.122E-09	**90%**	45.376E-09
25%	1.270E-09	**Range**	92.420E-09
Mean+3*StdDev	90.209E-09	**NOutsideSpec**	0
Mean-3*StdDev	-54.521E-09	**Cp**	>4.0000
Cpk	>4.0000	**Cpl**	>4.0000
Skew	-0.1419	**Cpu**	>4.0000
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

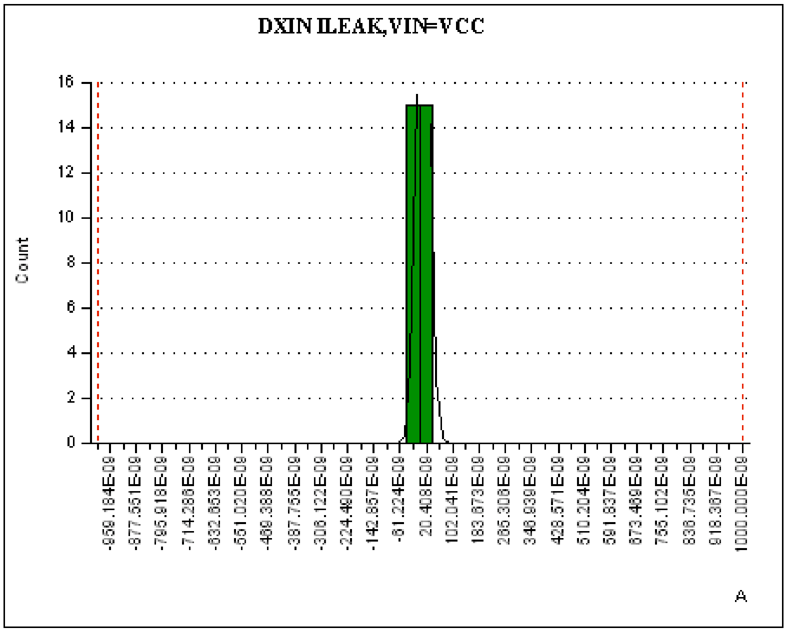
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=9.002, Test.Name=DXIN ILEAK,VIN=VCC



Statistics: (A)

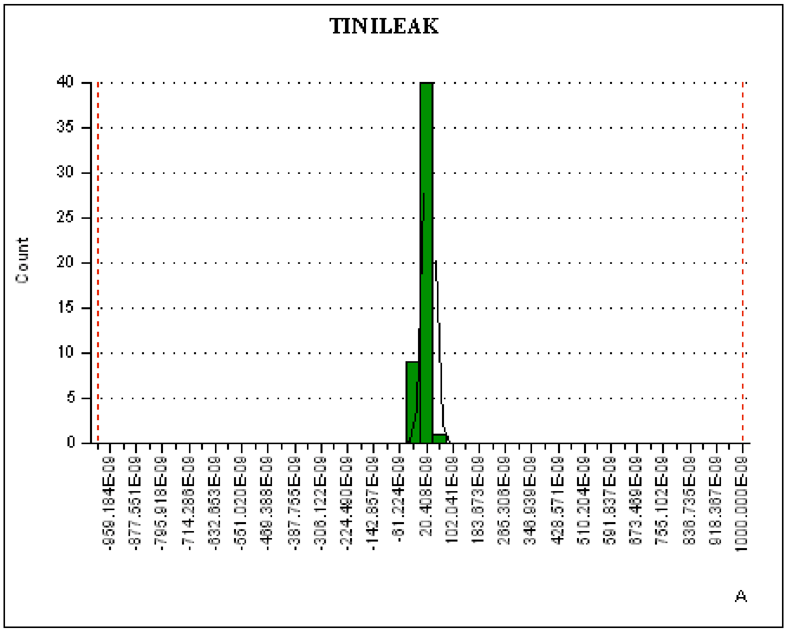
Min	-28.675E-09	**Skew**	0.0288
Max	29.613E-09	**StatHigh**	N/A
Mean	-833.476E-12	**StatLow**	N/A
StdDev	19.670E-09	**NWithinSpec**	30
25%	-17.400E-09	**NOutsideSpec**	0
Mean+3*StdDev	58.177E-09	**90%**	24.824E-09
		Range	58.288E-09
Mean-3*StdDev	-59.844E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=9.002, Test.Name=TIN ILEAK



Statistics: (A)

Min	-24.617E-09	**StatLow**	N/A
Max	48.323E-09	**NWithinSpec**	50
Mean	17.779E-09	**NOutsideSpec**	0
StdDev	16.857E-09	**90%**	34.886E-09
25%	13.025E-09	**Range**	72.940E-09
Mean+3*StdDev	68.350E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-32.792E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.9846		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

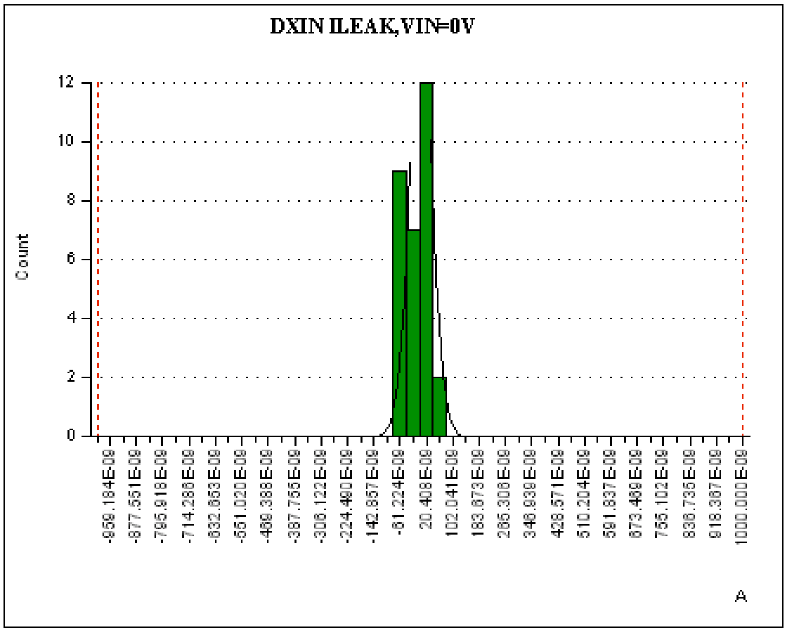
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=9.003, Test.Name=DXIN ILEAK,VIN=0V



Statistics: (A)

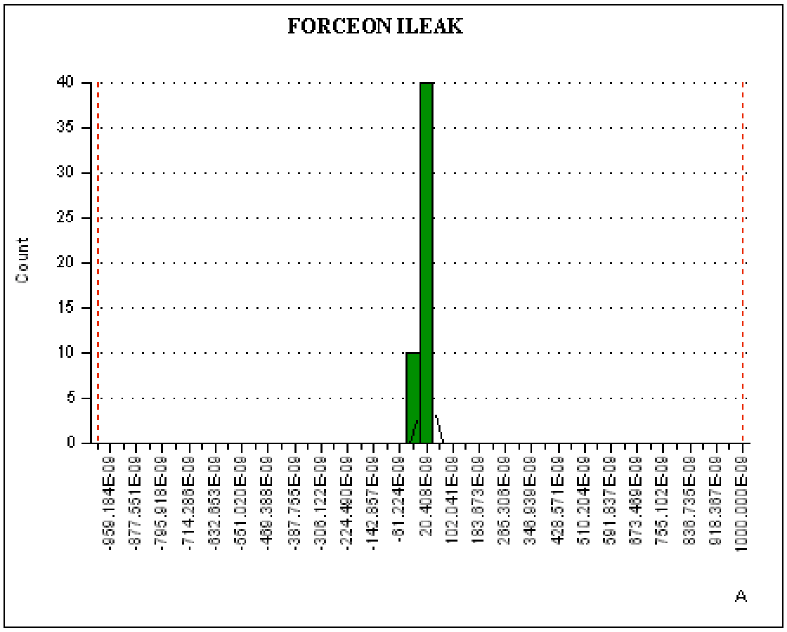
Min	-65.258E-09	**Skew**	-0.1138
Max	46.157E-09	**StatHigh**	N/A
Mean	-8.375E-09	**StatLow**	N/A
StdDev	35.119E-09	**NWithinSpec**	30
25%	-45.878E-09	**NOutsideSpec**	0
Mean+3*StdDev	96.983E-09	**90%**	35.398E-09
		Range	111.415E-09
Mean-3*StdDev	-113.733E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=9.003, Test.Name=FORCEON ILEAK



Statistics: (A)

Min	-29.599E-09	**StatLow**	N/A
Max	24.780E-09	**NWithinSpec**	50
Mean	10.455E-09	**NOutsideSpec**	0
StdDev	11.824E-09	**90%**	20.677E-09
25%	7.750E-09	**Range**	54.379E-09
Mean+3*StdDev	45.927E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-25.018E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-1.6368		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

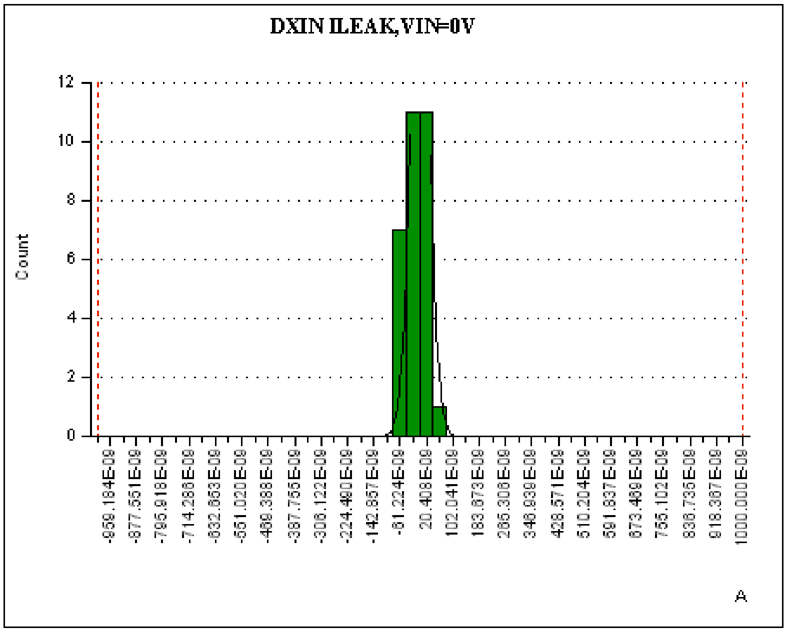
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=9.004, Test.Name=DXIN ILEAK,VIN=0V



Statistics: (A)

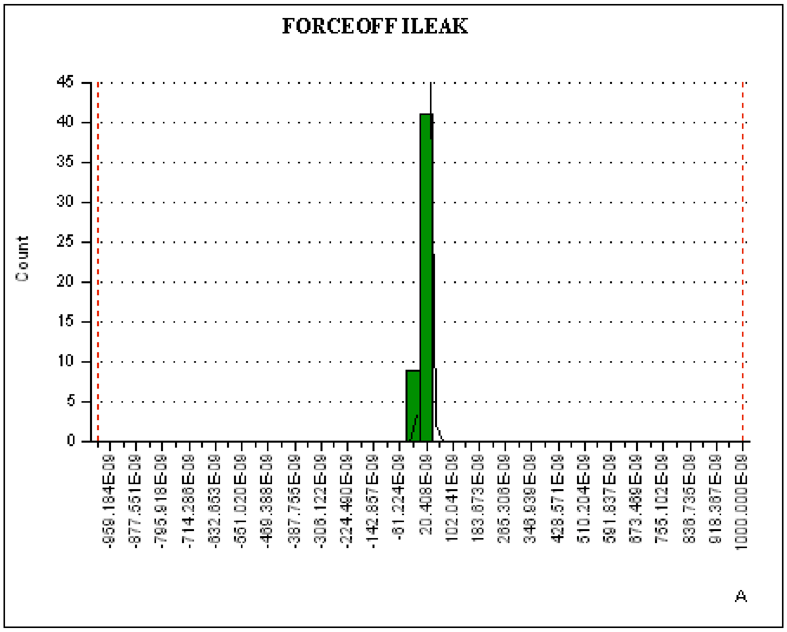
Min	-52.955E-09	**Skew**	0.2303
Max	43.208E-09	**StatHigh**	N/A
Mean	-10.981E-09	**StatLow**	N/A
StdDev	28.731E-09	**NWithinSpec**	30
25%	-39.911E-09	**NOutsideSpec**	0
Mean+3*StdDev	75.213E-09	**90%**	30.569E-09
		Range	96.164E-09
Mean-3*StdDev	-97.176E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=9.004, Test.Name=FORCEOFF ILEAK



Statistics: (A)

Min	-31.171E-09	**StatLow**	N/A
Max	22.655E-09	**NWithinSpec**	50
Mean	9.107E-09	**NOutsideSpec**	0
StdDev	11.783E-09	**90%**	20.457E-09
25%	3.688E-09	**Range**	53.826E-09
Mean+3*StdDev	44.455E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-26.242E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-1.4514		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

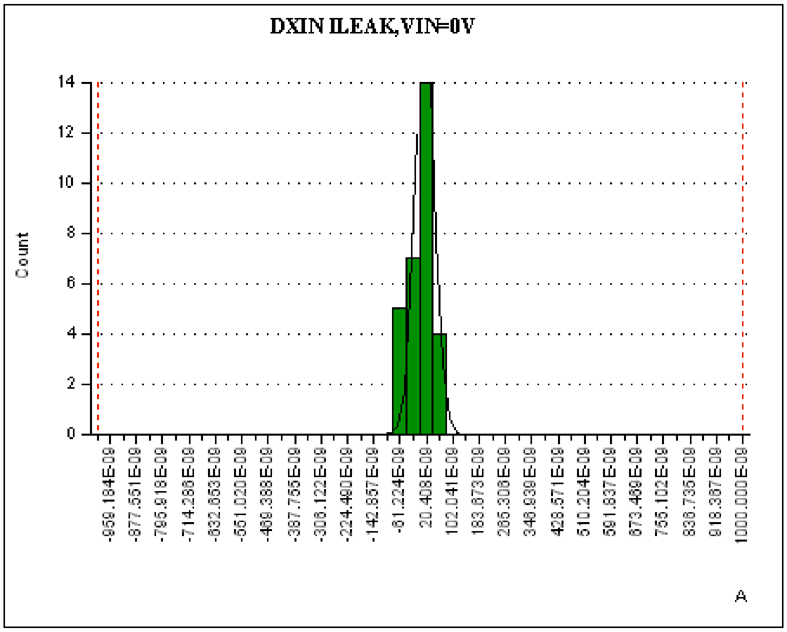
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=9.005, Test.Name=DXIN ILEAK,VIN=0V



Statistics: (A)

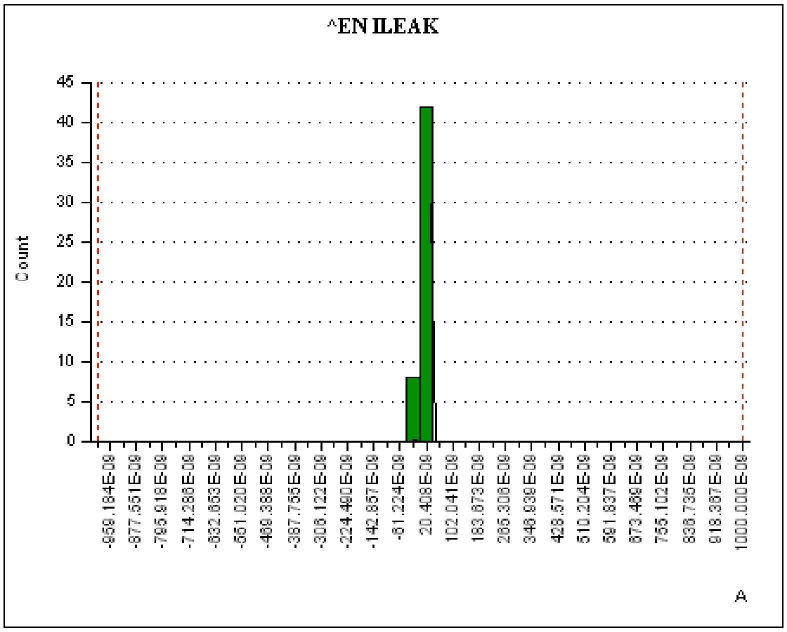
Min	-49.343E-09	**Skew**	-0.5018
Max	45.199E-09	**StatHigh**	N/A
Mean	3.658E-09	**StatLow**	N/A
StdDev	30.098E-09	**NWithinSpec**	30
25%	-7.560E-09	**NOutsideSpec**	0
Mean+3*StdDev	93.951E-09	**90%**	41.404E-09
		Range	94.542E-09
Mean-3*StdDev	-86.635E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=9.005, Test.Name=^EN ILEAK



Statistics: (A)

Min	-10.538E-09	**StatLow**	N/A
Max	22.765E-09	**NWithinSpec**	50
Mean	7.670E-09	**NOutsideSpec**	0
StdDev	7.773E-09	**90%**	15.194E-09
25%	3.594E-09	**Range**	33.303E-09
Mean+3*StdDev	30.989E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-15.650E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.7417		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

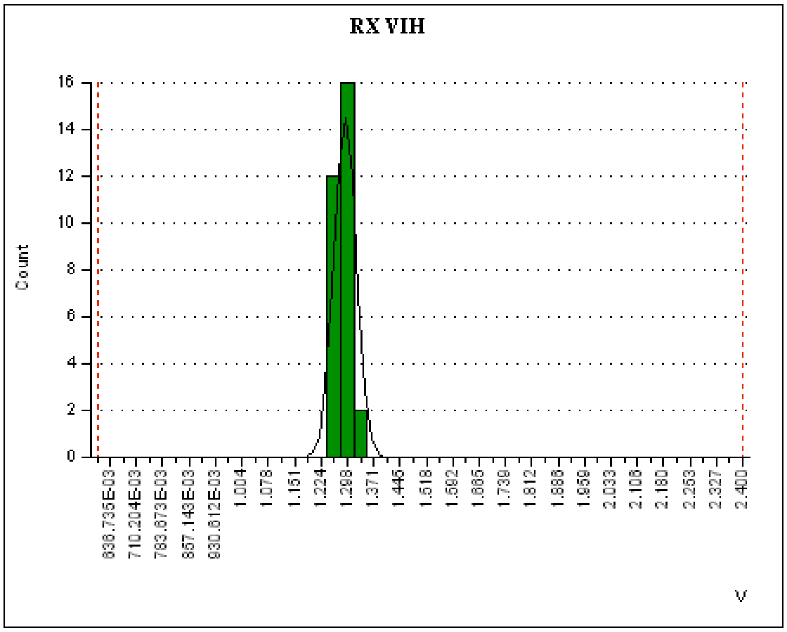
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.000, Test.Name=RX VIH



Statistics: (V)

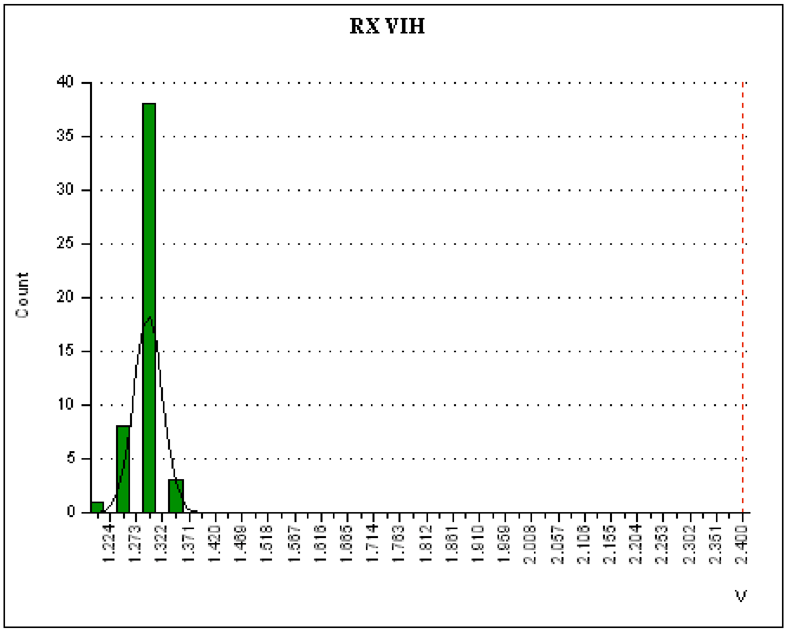
Min	1.250	**Skew**	0.2944
Max	1.350	**StatHigh**	N/A
Mean	1.283	**StatLow**	N/A
StdDev	30.324E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.374	**90%**	1.300
		Range	100.000E-03
Mean-3*StdDev	1.192	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.000, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.350	**NWithinSpec**	50
Mean	1.293	**NOutsideSpec**	0
StdDev	26.745E-03	**90%**	1.300
25%	1.300	**Range**	150.001E-03
Mean+3*StdDev	1.373	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.213	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.9687		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

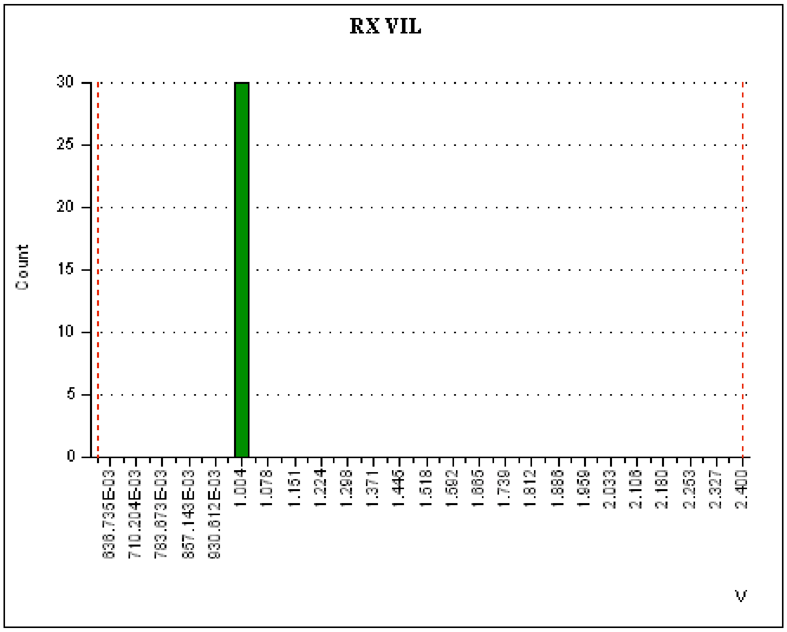
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.001, Test.Name=RX VIL



Statistics: (V)

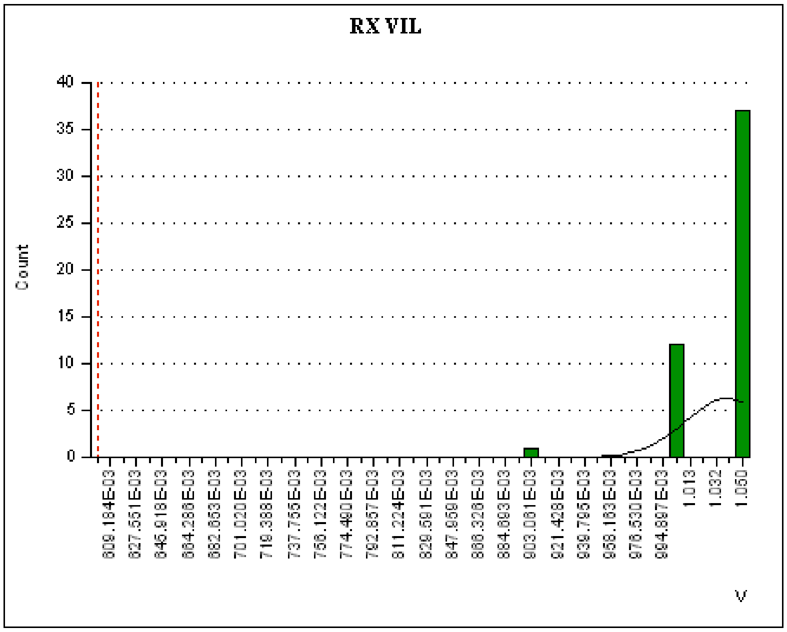
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	1000.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.001, Test.Name=RX VIL



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	50
Mean	1.035	**NOutsideSpec**	0
StdDev	29.014E-03	**90%**	1.050
25%	1000.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.122	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	947.956E-03	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-2.4805		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

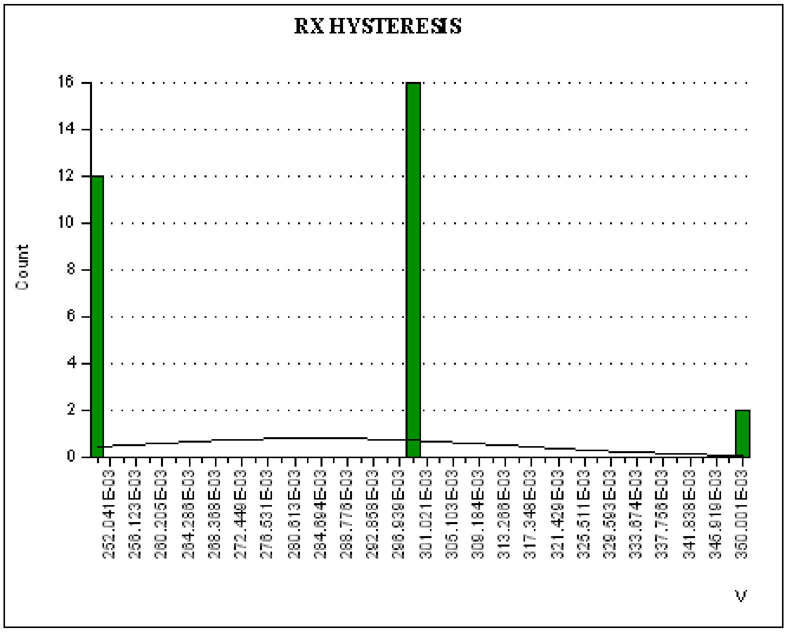
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.002, Test.Name=RX HYSTERESIS



Statistics: (V)

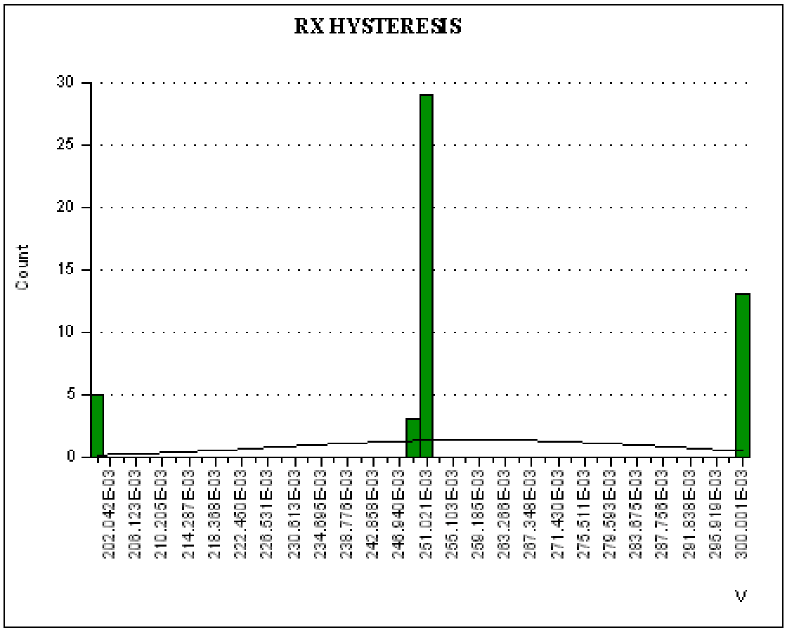
Min	250.000E-03	**Skew**	0.2944
Max	350.001E-03	**StatHigh**	N/A
Mean	283.334E-03	**StatLow**	N/A
StdDev	30.324E-03	**NWithinSpec**	N/A
25%	250.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	374.306E-03	**90%**	300.001E-03
		Range	100.000E-03
Mean-3*StdDev	192.362E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.002, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	200.001E-03	**StatLow**	N/A
Max	300.001E-03	**NWithinSpec**	N/A
Mean	258.001E-03	**NOutsideSpec**	N/A
StdDev	29.207E-03	**90%**	300.001E-03
25%	250.001E-03	**Range**	100.000E-03
Mean+3*StdDev	345.622E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	170.379E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0246		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

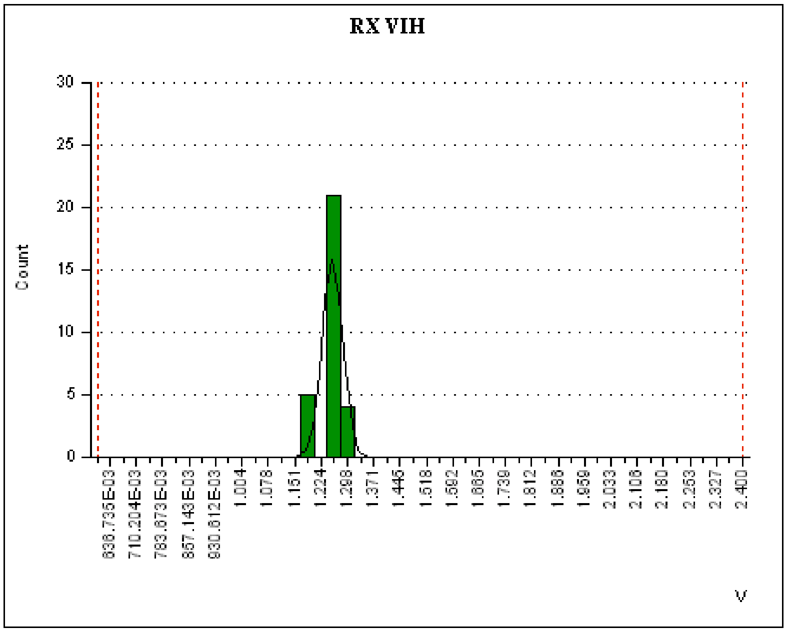
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.003, Test.Name=RX VIH



Statistics: (V)

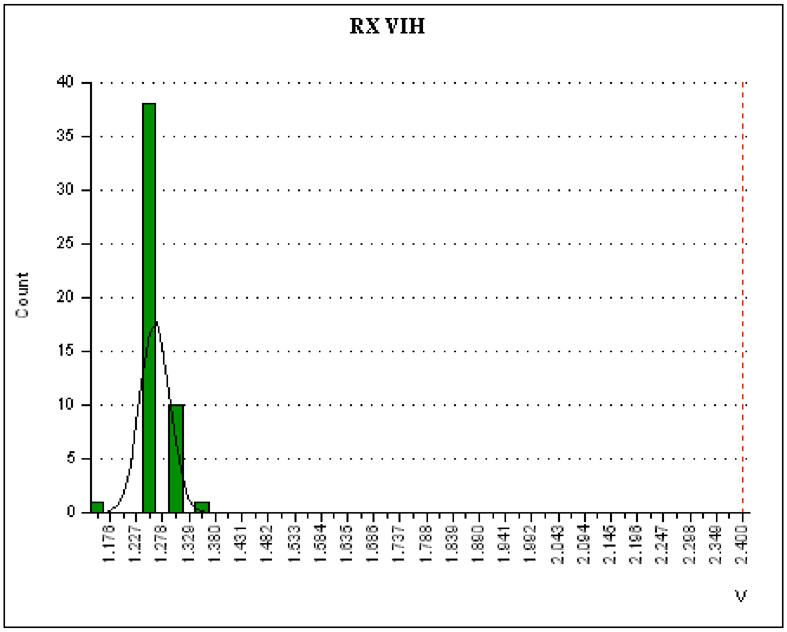
Min	1.200	**Skew**	-0.0220
Max	1.300	**StatHigh**	N/A
Mean	1.248	**StatLow**	N/A
StdDev	27.803E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.332	**90%**	1.300
		Range	100.000E-03
Mean-3*StdDev	1.165	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.003, Test.Name=RX VIH



Statistics: (V)

Min	1.150	**StatLow**	N/A
Max	1.350	**NWithinSpec**	50
Mean	1.260	**NOutsideSpec**	0
StdDev	28.572E-03	**90%**	1.300
25%	1.250	**Range**	200.001E-03
Mean+3*StdDev	1.346	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.174	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.0000		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

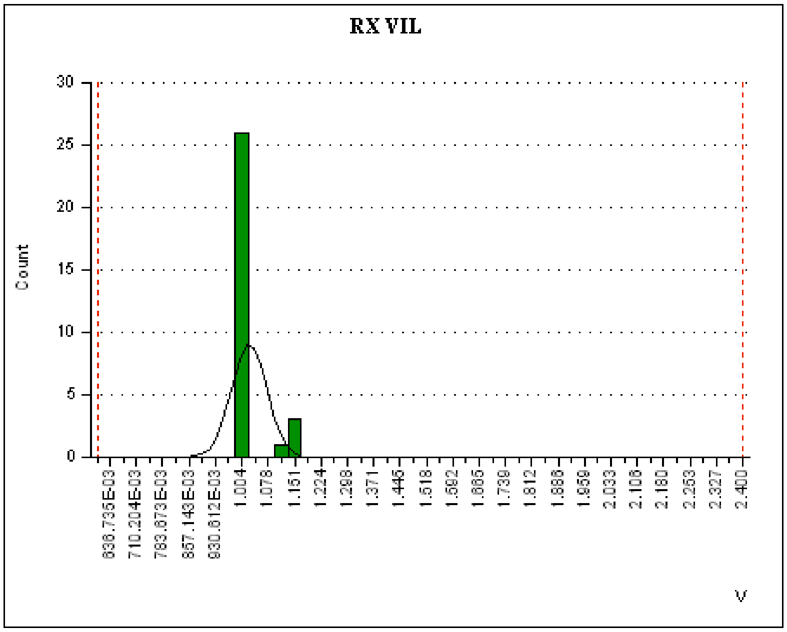
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.004, Test.Name=RX VIL



Statistics: (V)

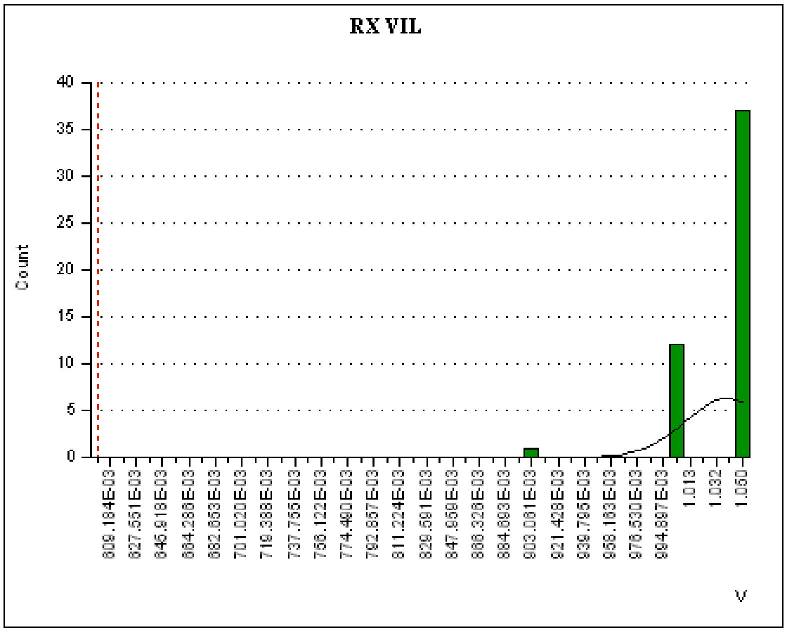
Min	1000.000E-03	**Skew**	2.3839
Max	1.150	**StatHigh**	N/A
Mean	1.018	**StatLow**	N/A
StdDev	48.215E-03	**NWithinSpec**	30
25%	1000.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	1.163	**90%**	1.125
		Range	150.000E-03
Mean-3*StdDev	873.687E-03	**NOutsideSpec**	0
Cpk	2.8921		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.004, Test.Name=RX VIL



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	50
Mean	1.035	**NOutsideSpec**	0
StdDev	29.014E-03	**90%**	1.050
25%	1000.000E-03	**Range**	150.000E-03
Mean+3*StdDev	1.122	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	947.956E-03	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-2.4805		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

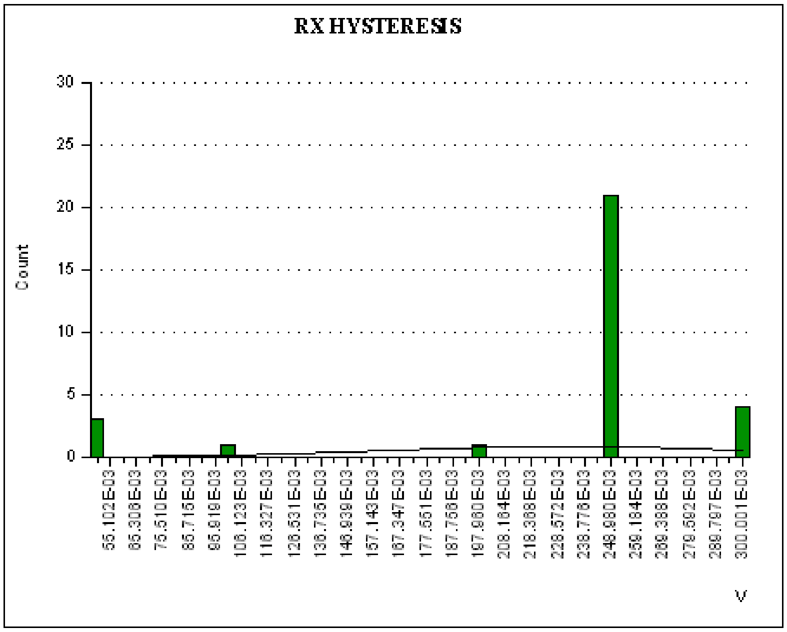
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.005, Test.Name=RX HYSTERESIS



Statistics: (V)

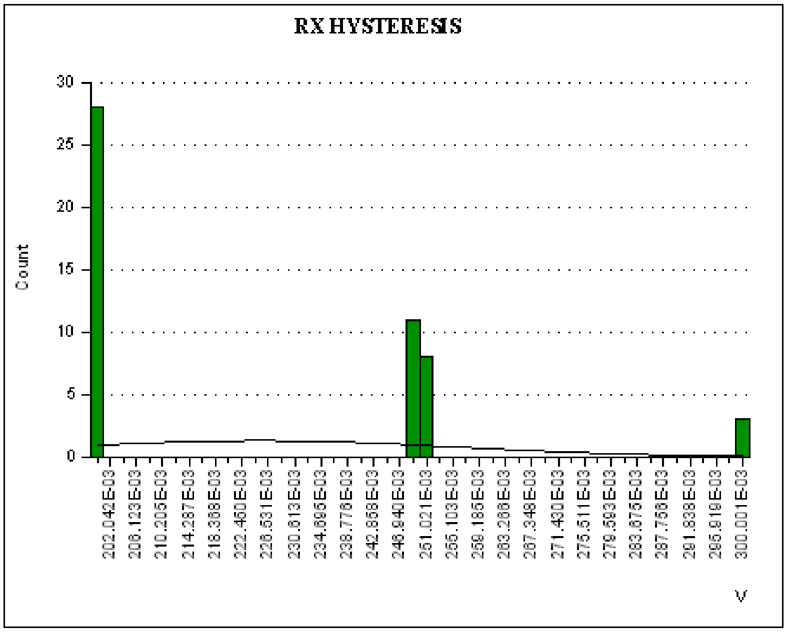
Min	50.000E-03	**Skew**	-1.9398
Max	300.001E-03	**StatHigh**	N/A
Mean	230.000E-03	**StatLow**	N/A
StdDev	70.221E-03	**NWithinSpec**	N/A
25%	250.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	440.665E-03	**90%**	300.001E-03
		Range	250.000E-03
Mean-3*StdDev	19.336E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.005, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	200.001E-03	**StatLow**	N/A
Max	300.001E-03	**NWithinSpec**	N/A
Mean	225.001E-03	**NOutsideSpec**	N/A
StdDev	30.723E-03	**90%**	250.001E-03
25%	200.001E-03	**Range**	100.000E-03
Mean+3*StdDev	317.168E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	132.833E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.8247		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

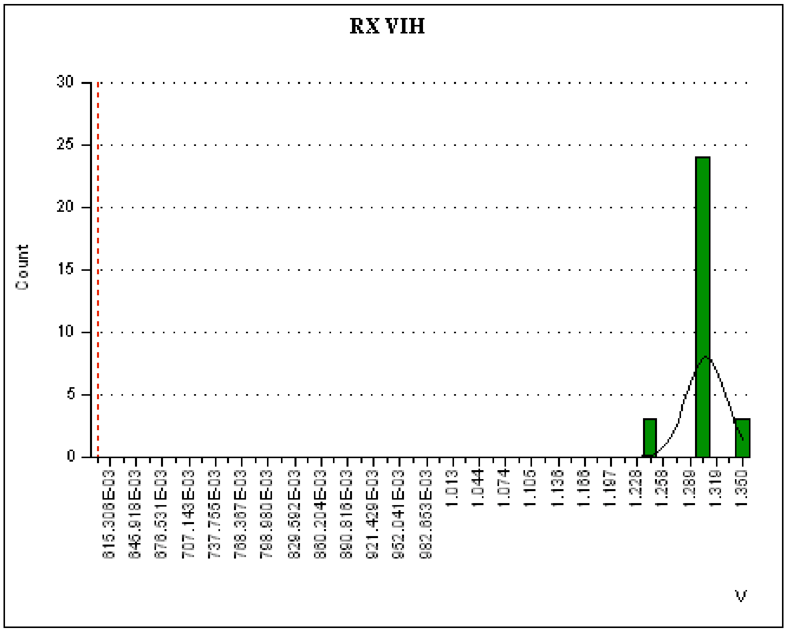
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.006, Test.Name=RX VIH



Statistics: (V)

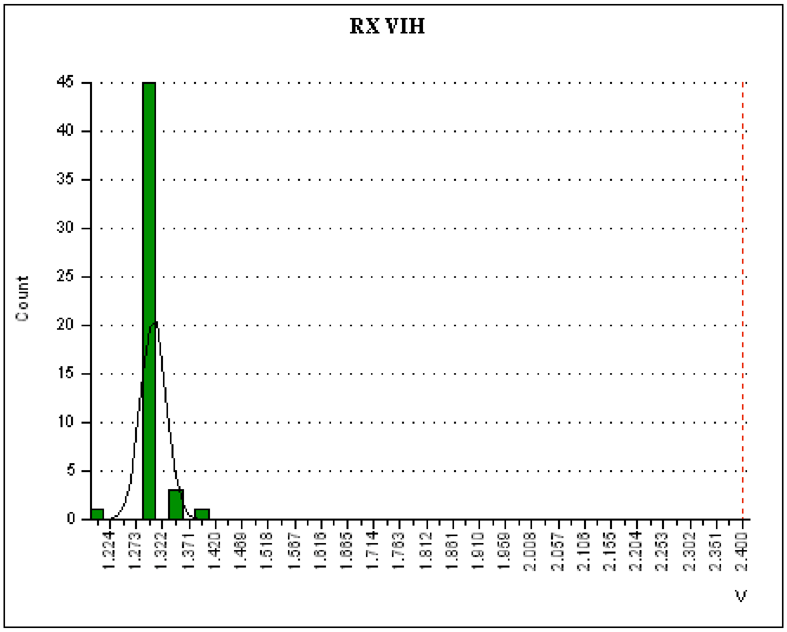
Min	1.250	**Skew**	0.0000
Max	1.350	**StatHigh**	N/A
Mean	1.300	**StatLow**	N/A
StdDev	22.743E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.368	**90%**	1.325
		Range	100.000E-03
Mean-3*StdDev	1.232	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.006, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.400	**NWithinSpec**	50
Mean	1.303	**NOutsideSpec**	0
StdDev	23.496E-03	**90%**	1.300
25%	1.300	**Range**	200.000E-03
Mean+3*StdDev	1.373	**NOutsideSpec**	0
Mean-3*StdDev	1.233	**Cp**	N/A
		Cpl	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.2134		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

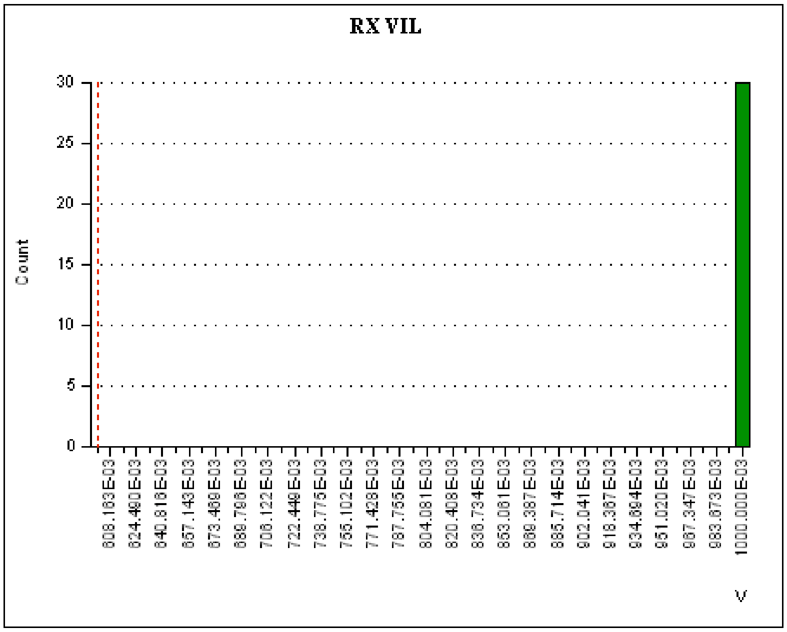
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.007, Test.Name=RX VIL



Statistics: (V)

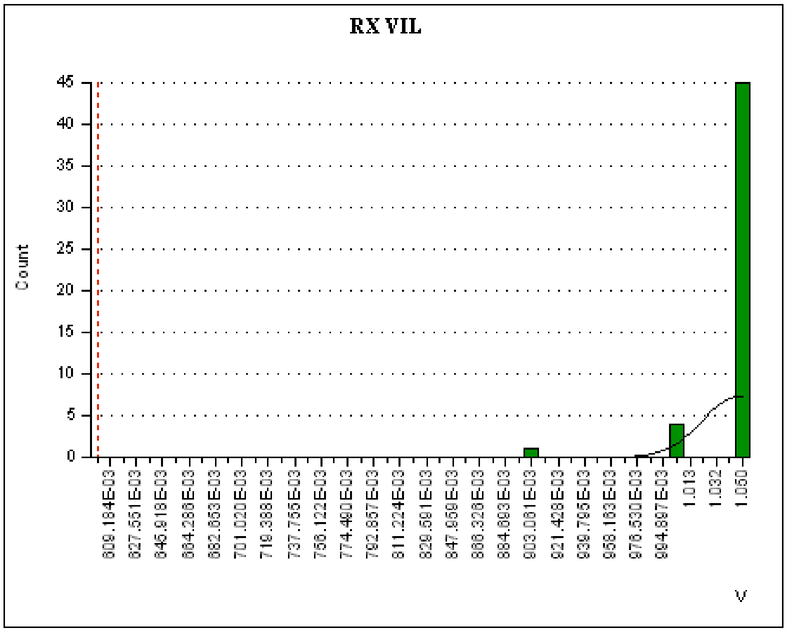
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	1000.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.007, Test.Name=RX VIL



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	50
Mean	1.043	**NOutsideSpec**	0
StdDev	24.764E-03	**90%**	1.050
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.117	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	968.707E-03	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-4.5168		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

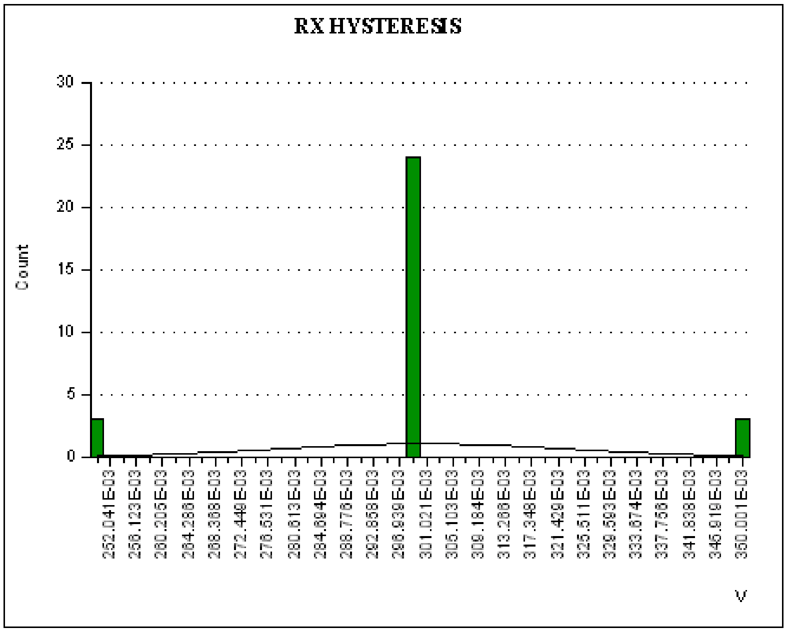
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.008, Test.Name=RX HYSTERESIS



Statistics: (V)

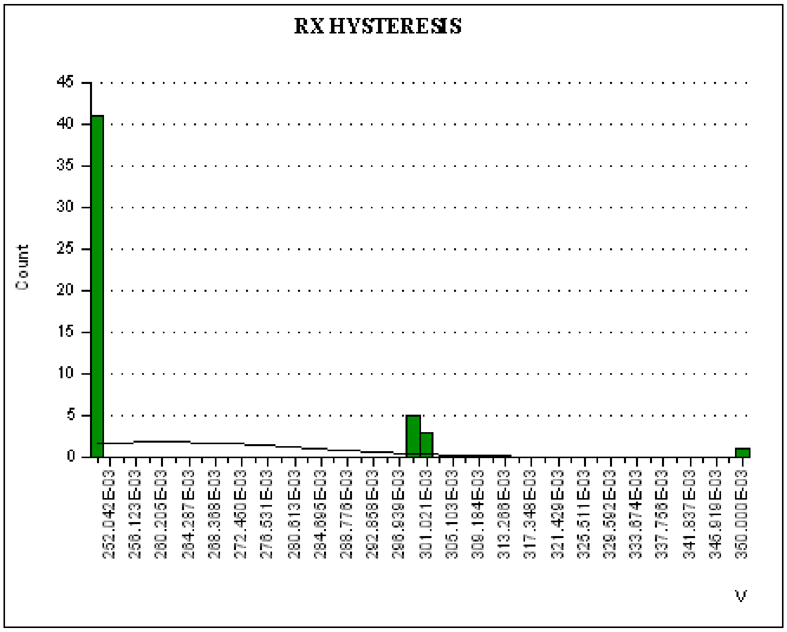
Min	250.000E-03	**Skew**	0.0000
Max	350.001E-03	**StatHigh**	N/A
Mean	300.001E-03	**StatLow**	N/A
StdDev	22.743E-03	**NWithinSpec**	N/A
25%	300.001E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	368.230E-03	**90%**	325.001E-03
		Range	100.000E-03
Mean-3*StdDev	231.772E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.008, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	250.001E-03	**StatLow**	N/A
Max	350.000E-03	**NWithinSpec**	N/A
Mean	260.001E-03	**NOutsideSpec**	N/A
StdDev	22.588E-03	**90%**	300.001E-03
25%	250.001E-03	**Range**	99.999E-03
Mean+3*StdDev	327.764E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	192.238E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.2136		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

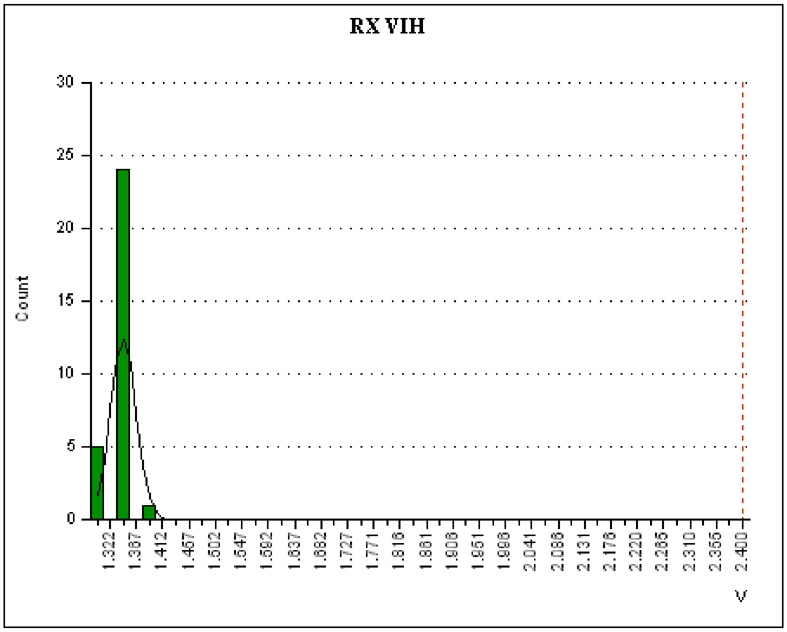
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.009, Test.Name=RX VIH



Statistics: (V)

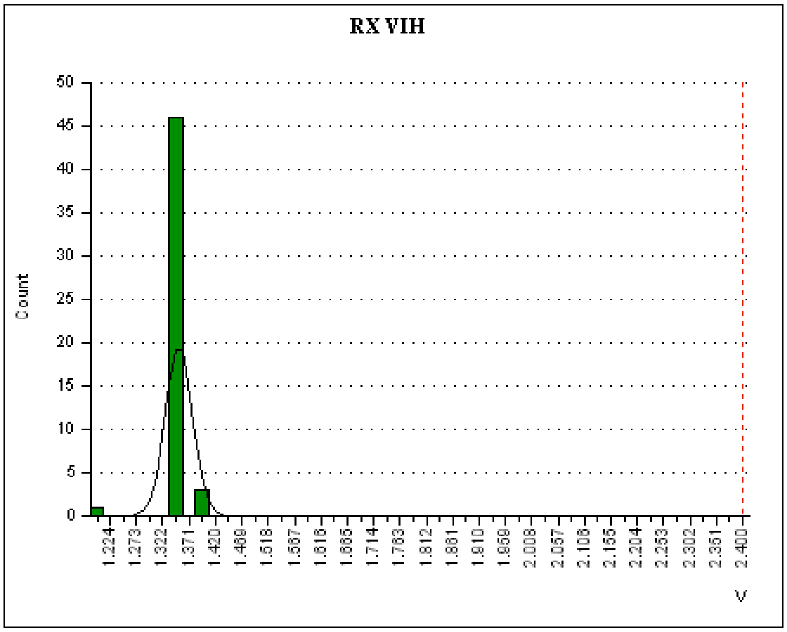
Min	1.300	**Skew**	-0.7865
Max	1.400	**StatHigh**	N/A
Mean	1.343	**StatLow**	N/A
StdDev	21.709E-03	**NWithinSpec**	30
25%	1.350	**NOutsideSpec**	0
Mean+3*StdDev	1.408	**90%**	1.350
		Range	99.999E-03
Mean-3*StdDev	1.278	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.009, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.400	**NWithinSpec**	50
Mean	1.350	**NOutsideSpec**	0
StdDev	24.744E-03	**90%**	1.350
25%	1.350	**Range**	200.000E-03
Mean+3*StdDev	1.424	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.276	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-4.2099		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

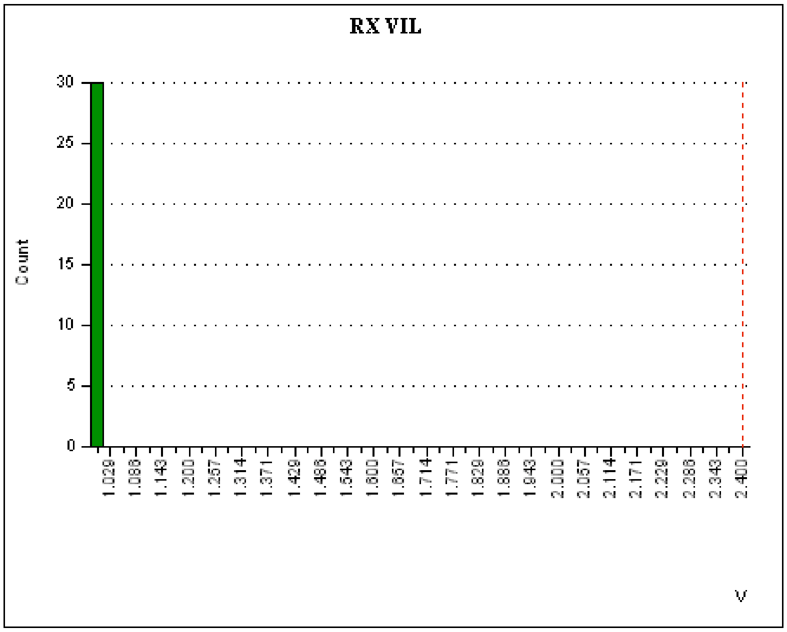
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.010, Test.Name=RX VIL



Statistics: (V)

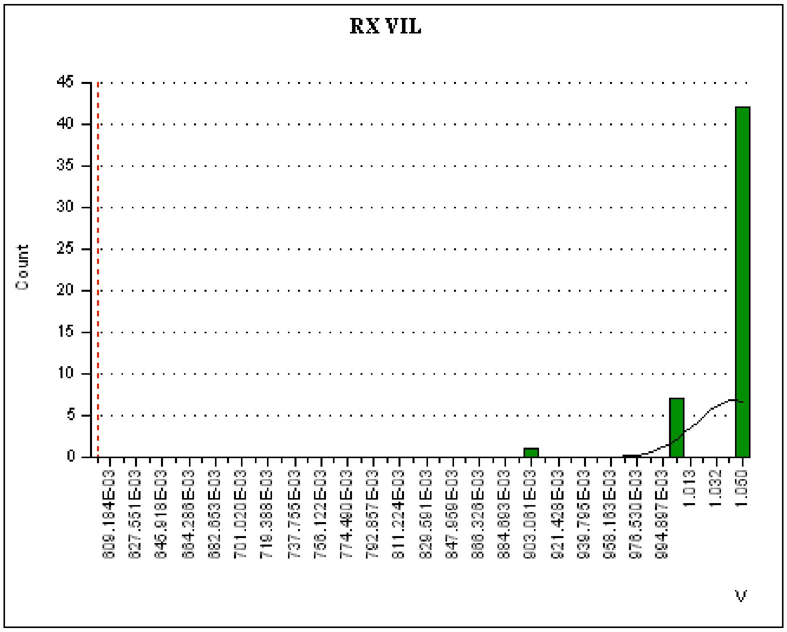
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	1000.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.010, Test.Name=RX VIL



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	50
Mean	1.040	**NOutsideSpec**	0
StdDev	26.726E-03	**90%**	1.050
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.120	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	959.821E-03	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-3.5078		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

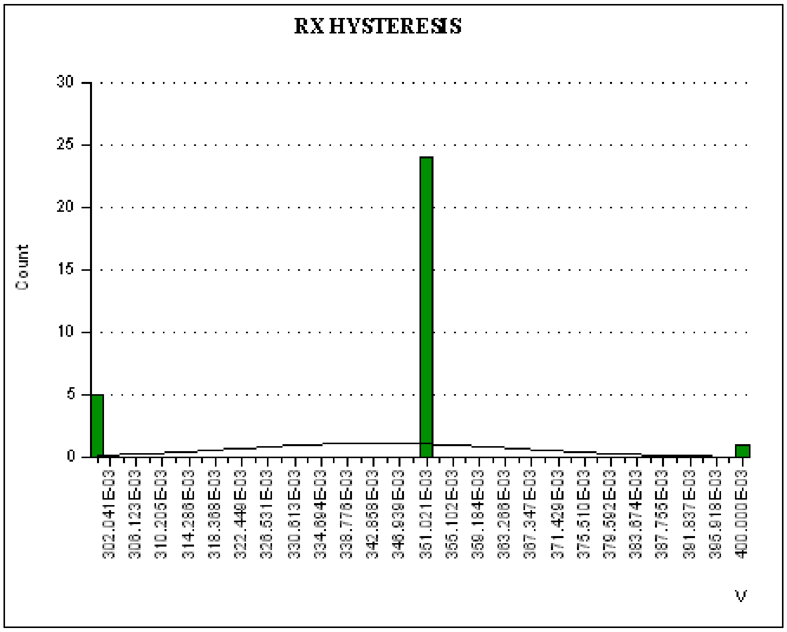
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.011, Test.Name=RX HYSTERESIS



Statistics: (V)

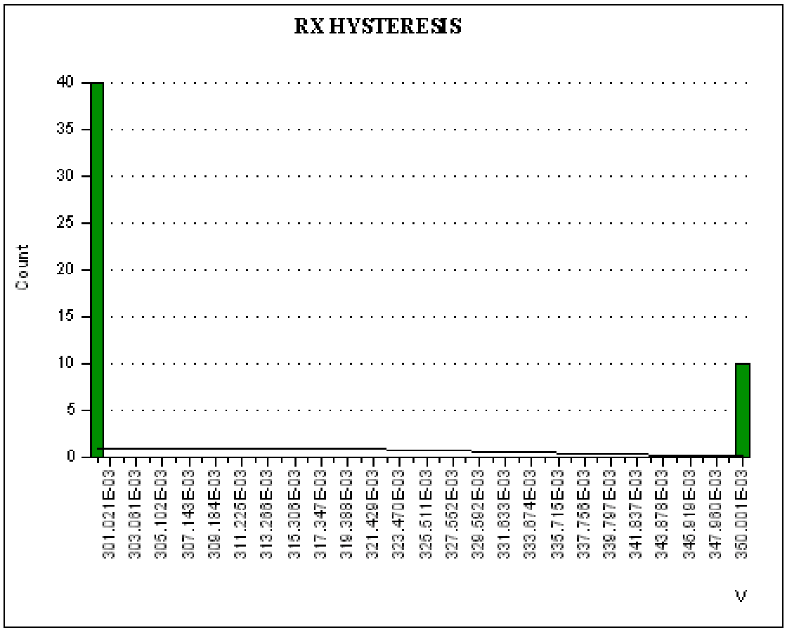
Min	300.001E-03	**Skew**	-0.7865
Max	400.000E-03	**StatHigh**	N/A
Mean	343.334E-03	**StatLow**	N/A
StdDev	21.709E-03	**NWithinSpec**	N/A
25%	350.001E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	408.460E-03	**90%**	350.001E-03
		Range	99.999E-03
Mean-3*StdDev	278.208E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.011, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	300.000E-03	**StatLow**	N/A
Max	350.001E-03	**NWithinSpec**	N/A
Mean	310.001E-03	**NOutsideSpec**	N/A
StdDev	20.203E-03	**90%**	350.001E-03
25%	300.001E-03	**Range**	50.001E-03
Mean+3*StdDev	370.610E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	249.392E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.5468		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

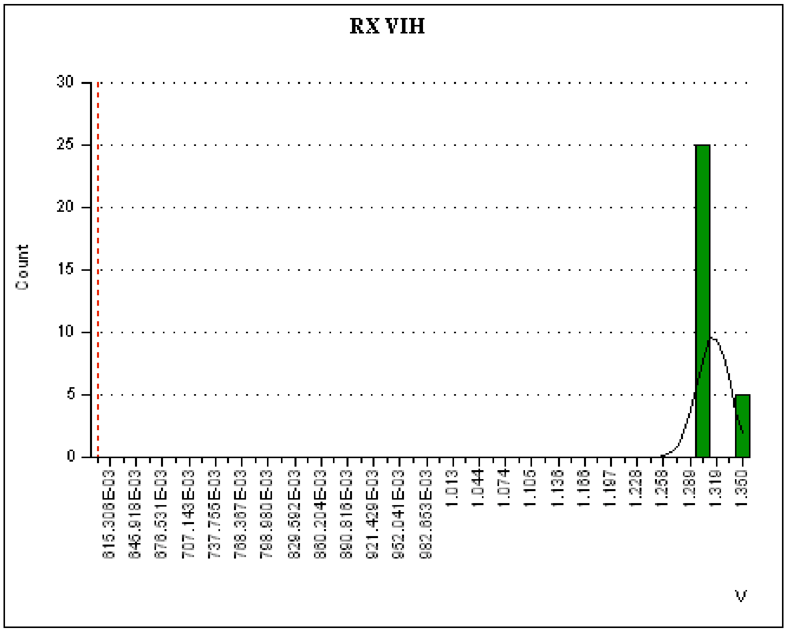
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.012, Test.Name=RX VIH



Statistics: (V)

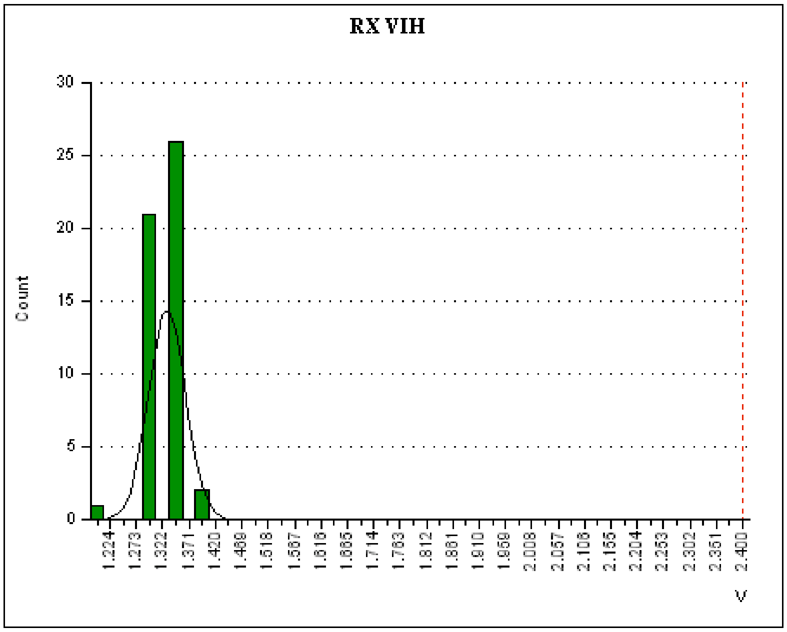
Min	1.300	**Skew**	1.8844
Max	1.350	**StatHigh**	N/A
Mean	1.308	**StatLow**	N/A
StdDev	18.953E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.365	**90%**	1.350
		Range	50.000E-03
Mean-3*StdDev	1.251	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.012, Test.Name=RX VIH



Statistics: (V)

Min	1.200	**StatLow**	N/A
Max	1.400	**NWithinSpec**	50
Mean	1.328	**NOutsideSpec**	0
StdDev	33.746E-03	**90%**	1.350
25%	1.300	**Range**	200.000E-03
Mean+3*StdDev	1.429	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.227	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.8491		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

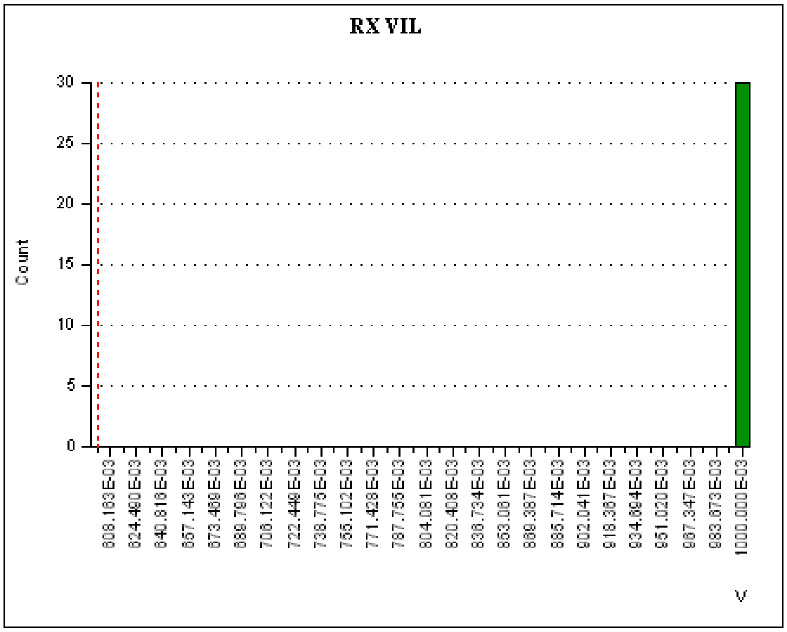
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.013, Test.Name=RX VIL



Statistics: (V)

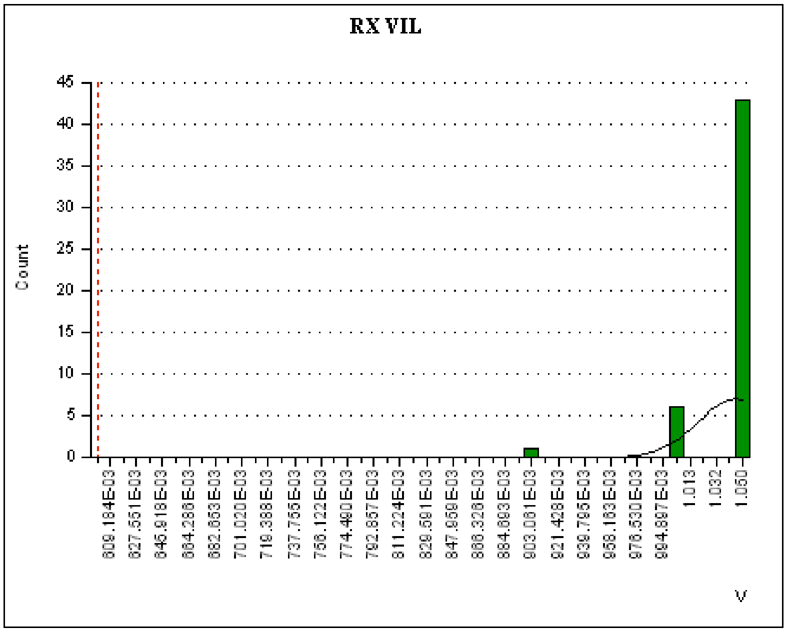
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	30
25%	1000.000E-03	**NOutsideSpec**	0
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	0
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.013, Test.Name=RX VIL



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	50
Mean	1.041	**NOutsideSpec**	0
StdDev	26.128E-03	**90%**	1.050
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.119	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	962.617E-03	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-3.7966		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

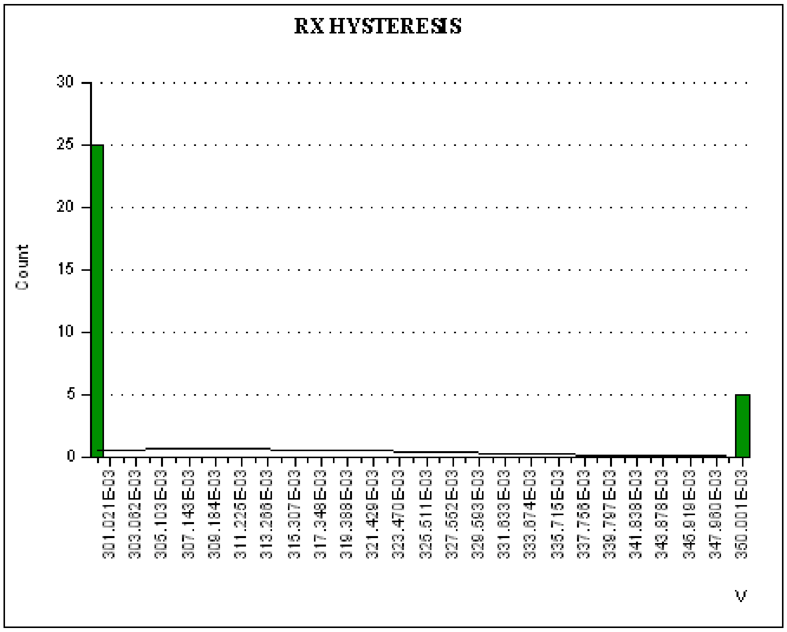
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=10.014, Test.Name=RX HYSTERESIS



Statistics: (V)

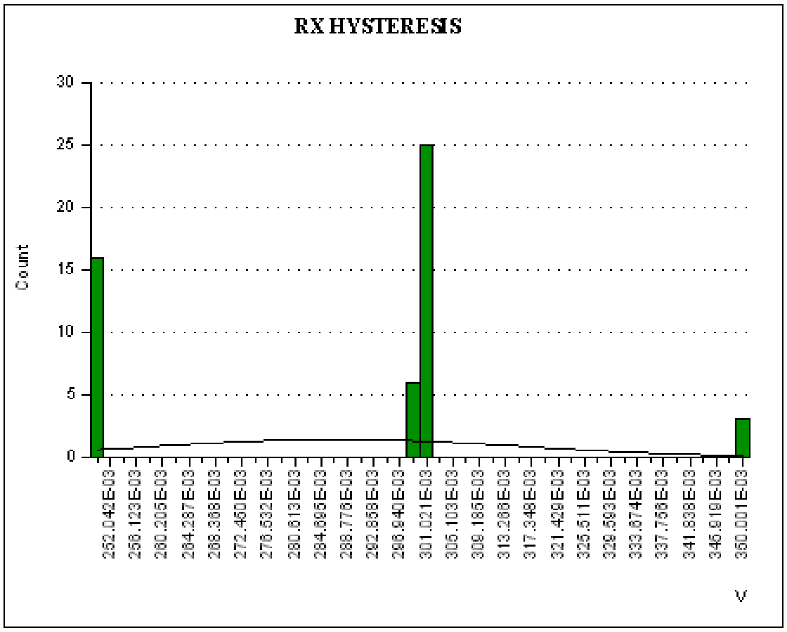
Min	300.001E-03	**Skew**	1.8844
Max	350.001E-03	**StatHigh**	N/A
Mean	308.334E-03	**StatLow**	N/A
StdDev	18.953E-03	**NWithinSpec**	N/A
25%	300.001E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	365.192E-03	**90%**	350.001E-03
		Range	50.000E-03
Mean-3*StdDev	251.476E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=10.014, Test.Name=RX HYSTERESIS



Statistics: (V)

Min	250.001E-03	**StatLow**	N/A
Max	350.001E-03	**NWithinSpec**	N/A
Mean	287.001E-03	**NOutsideSpec**	N/A
StdDev	28.230E-03	**90%**	300.001E-03
25%	250.001E-03	**Range**	100.000E-03
Mean+3*StdDev	371.691E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	202.311E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.0074		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

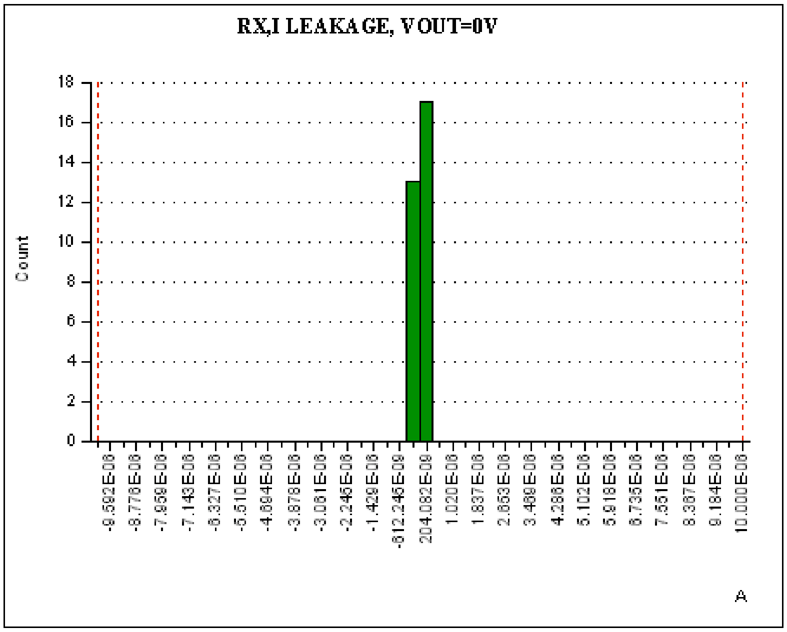
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.000, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

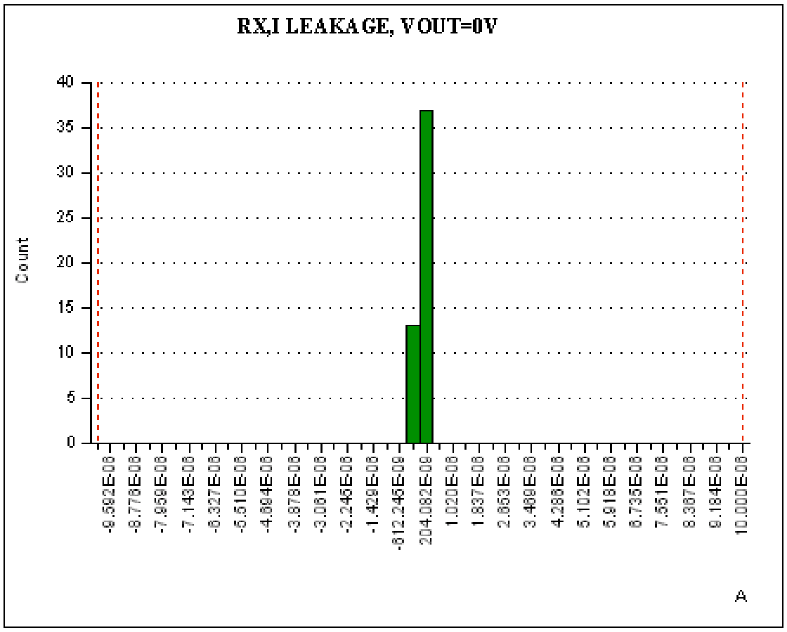
Min	-13.702E-09	**Skew**	0.1467
Max	15.967E-09	**StatHigh**	N/A
Mean	856.326E-12	**StatLow**	N/A
StdDev	7.939E-09	**NWithinSpec**	30
25%	-5.353E-09	**NOutsideSpec**	0
Mean+3*StdDev	24.674E-09	**90%**	13.081E-09
		Range	29.669E-09
Mean-3*StdDev	-22.961E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.000, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-11.253E-09	**StatLow**	N/A
Max	11.790E-09	**NWithinSpec**	50
Mean	3.819E-09	**NOutsideSpec**	0
StdDev	5.713E-09	**90%**	10.028E-09
25%	-157.428E-12	**Range**	23.043E-09
Mean+3*StdDev	20.959E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-13.320E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.7614		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

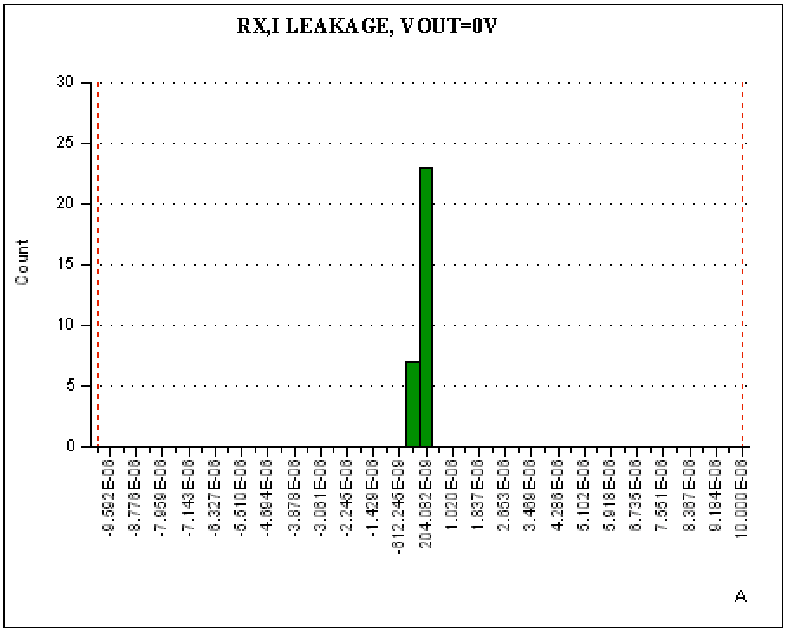
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.001, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

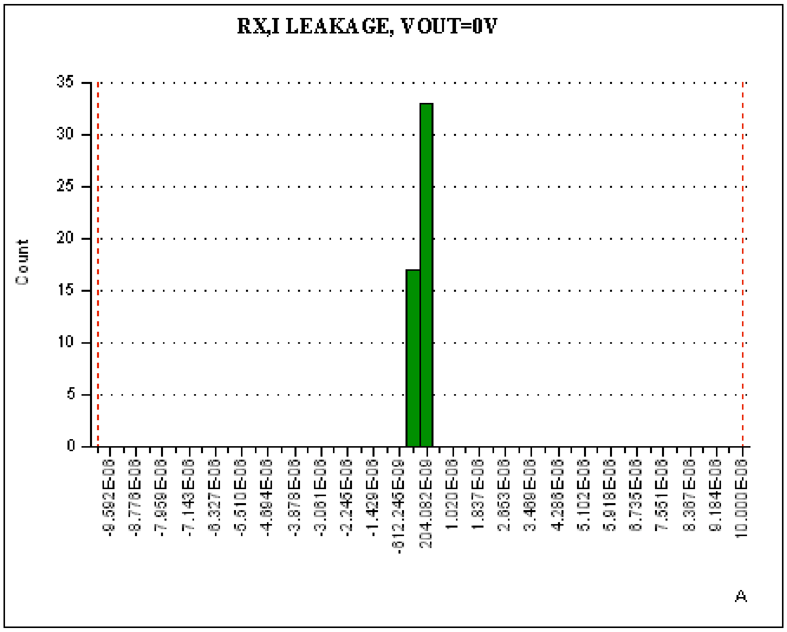
Min	-12.057E-09	**Skew**	-0.2592
Max	15.158E-09	**StatHigh**	N/A
Mean	3.556E-09	**StatLow**	N/A
StdDev	6.896E-09	**NWithinSpec**	30
25%	147.641E-12	**NOutsideSpec**	0
Mean+3*StdDev	24.245E-09	**90%**	13.597E-09
		Range	27.215E-09
Mean-3*StdDev	-17.133E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.001, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-11.997E-09	**StatLow**	N/A
Max	18.371E-09	**NWithinSpec**	50
Mean	3.332E-09	**NOutsideSpec**	0
StdDev	8.290E-09	**90%**	13.854E-09
25%	-4.906E-09	**Range**	30.367E-09
Mean+3*StdDev	28.203E-09	**NOutsideSpec**	0
Mean-3*StdDev	-21.538E-09	**Cp**	>4.0000
Cpk	>4.0000	**Cpl**	>4.0000
Skew	-0.1218	**Cpu**	>4.0000
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

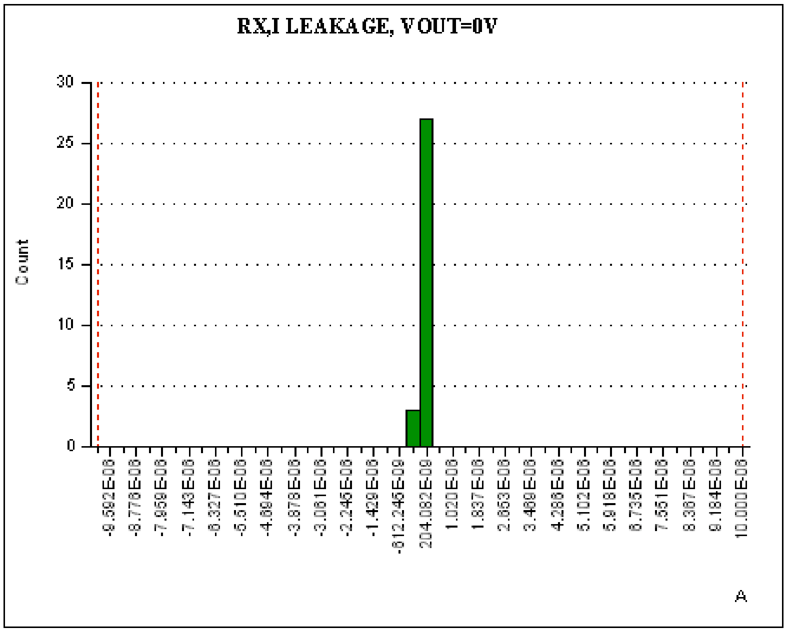
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.002, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

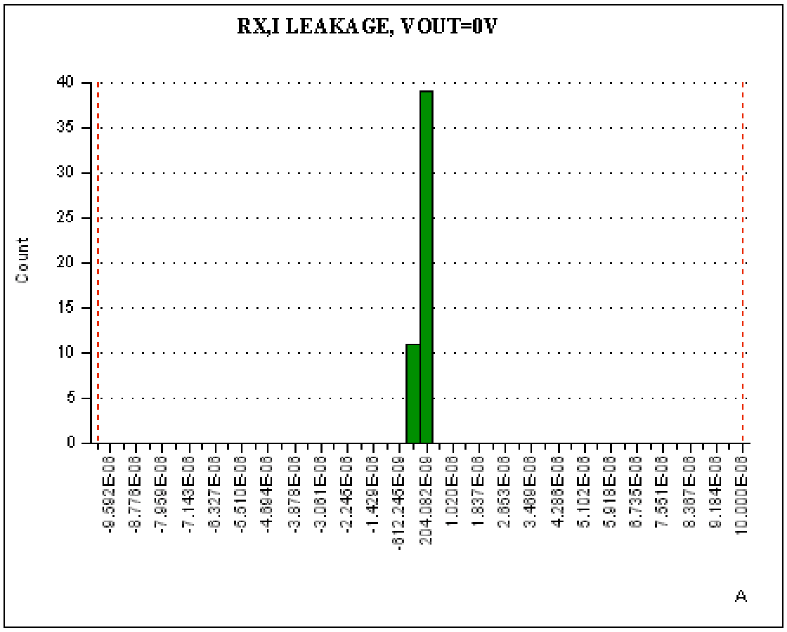
Min	-9.036E-09	**Skew**	-0.7742
Max	16.018E-09	**StatHigh**	N/A
Mean	6.476E-09	**StatLow**	N/A
StdDev	5.804E-09	**NWithinSpec**	30
25%	4.253E-09	**NOutsideSpec**	0
Mean+3*StdDev	23.889E-09	**90%**	14.028E-09
		Range	25.054E-09
Mean-3*StdDev	-10.937E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.002, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-10.862E-09	**StatLow**	N/A
Max	24.937E-09	**NWithinSpec**	50
Mean	4.598E-09	**NOutsideSpec**	0
StdDev	7.003E-09	**90%**	12.554E-09
25%	1.039E-09	**Range**	35.800E-09
Mean+3*StdDev	25.606E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-16.411E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	0.0116		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

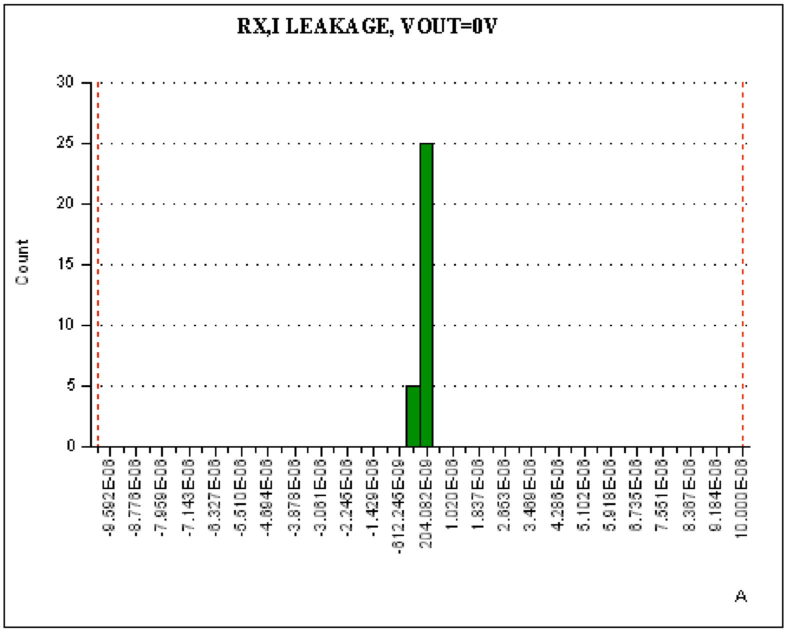
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.003, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

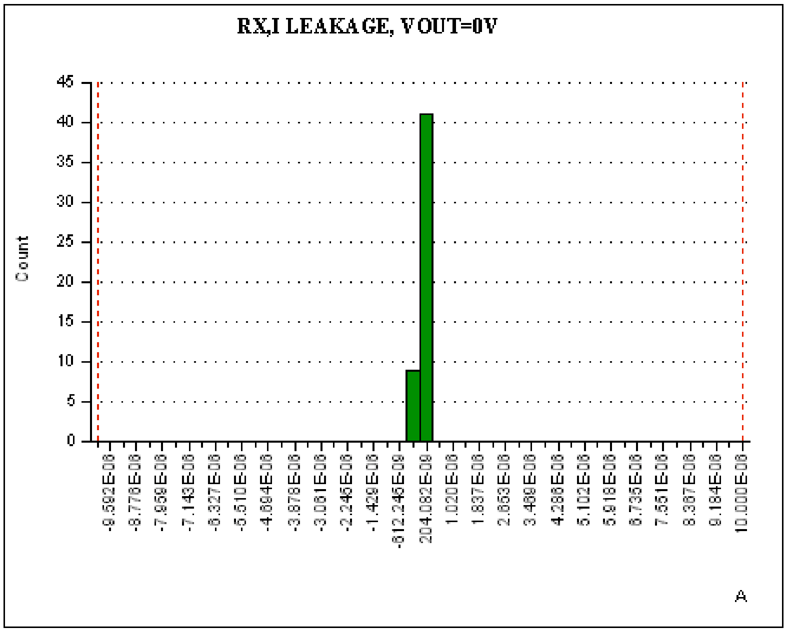
Min	-4.026E-09	**Skew**	-0.4958
Max	12.997E-09	**StatHigh**	N/A
Mean	5.972E-09	**StatLow**	N/A
StdDev	5.030E-09	**NWithinSpec**	30
25%	2.384E-09	**NOutsideSpec**	0
Mean+3*StdDev	21.062E-09	**90%**	11.768E-09
		Range	17.022E-09
Mean-3*StdDev	-9.118E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.003, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-7.970E-09	**StatLow**	N/A
Max	23.252E-09	**NWithinSpec**	50
Mean	6.505E-09	**NOutsideSpec**	0
StdDev	5.986E-09	**90%**	13.385E-09
25%	2.320E-09	**Range**	31.222E-09
Mean+3*StdDev	24.463E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-11.454E-09	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.0855		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

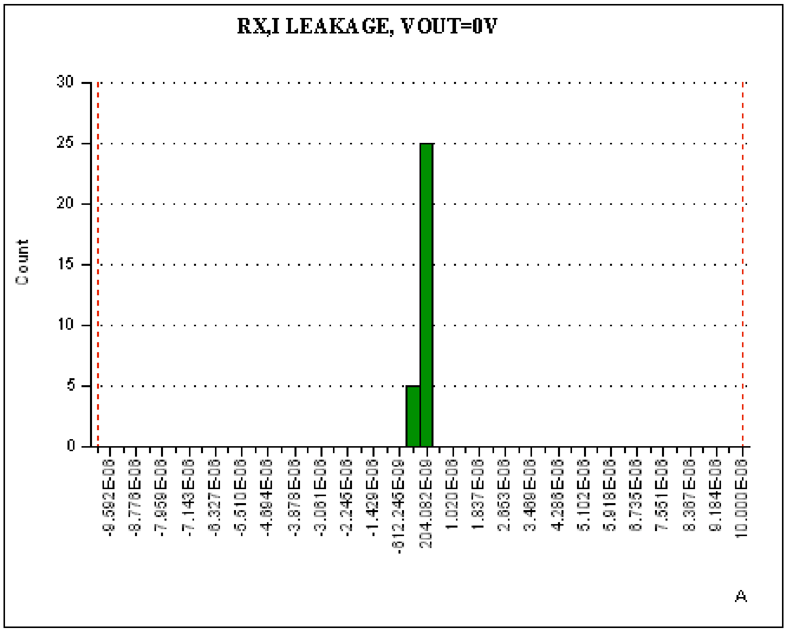
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.004, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

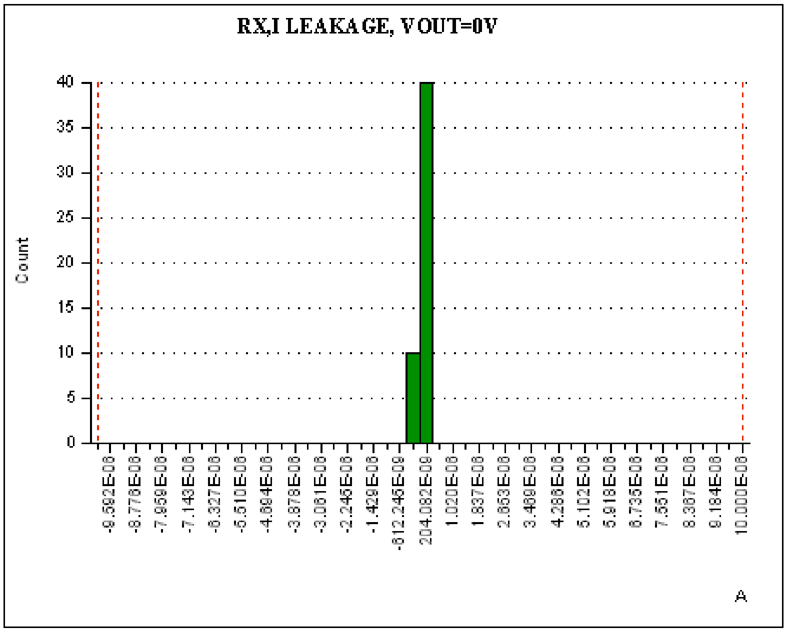
Min	-6.359E-09	**Skew**	-0.5582
Max	14.322E-09	**StatHigh**	N/A
Mean	6.047E-09	**StatLow**	N/A
StdDev	5.343E-09	**NWithinSpec**	30
25%	2.852E-09	**NOutsideSpec**	0
Mean+3*StdDev	22.077E-09	**90%**	12.898E-09
		Range	20.681E-09
Mean-3*StdDev	-9.983E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.004, Test.Name=RX,I LEAKAGE, VOUT=0V



Statistics: (A)

Min	-11.106E-09	**StatLow**	N/A
Max	23.472E-09	**NWithinSpec**	50
Mean	4.944E-09	**NOutsideSpec**	0
StdDev	7.872E-09	**90%**	12.976E-09
25%	1.587E-09	**Range**	34.579E-09
Mean+3*StdDev	28.560E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-18.673E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.4739		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

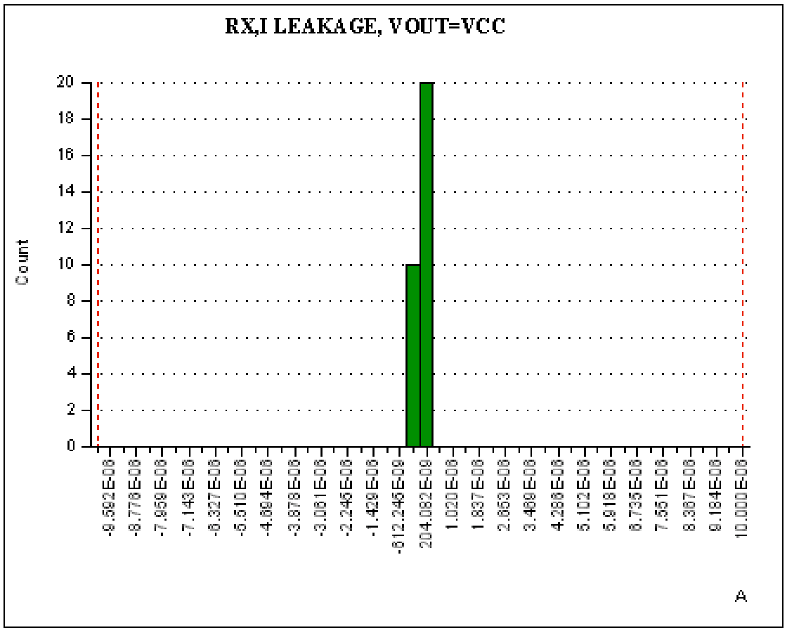
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.005, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

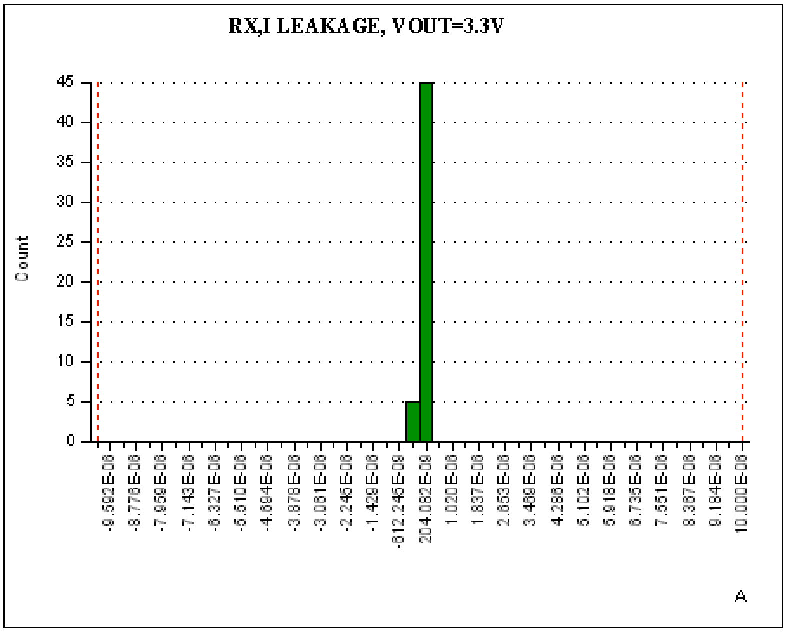
Min	-10.215E-09	**Skew**	-0.1677
Max	21.765E-09	**StatHigh**	N/A
Mean	5.392E-09	**StatLow**	N/A
StdDev	9.246E-09	**NWithinSpec**	30
25%	-3.385E-09	**NOutsideSpec**	0
Mean+3*StdDev	33.131E-09	**90%**	14.875E-09
		Range	31.981E-09
Mean-3*StdDev	-22.346E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.005, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-9.739E-09	**StatLow**	N/A
Max	22.362E-09	**NWithinSpec**	50
Mean	11.114E-09	**NOutsideSpec**	0
StdDev	7.227E-09	**90%**	19.018E-09
25%	7.777E-09	**Range**	32.101E-09
Mean+3*StdDev	32.796E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-10.568E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.9501		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

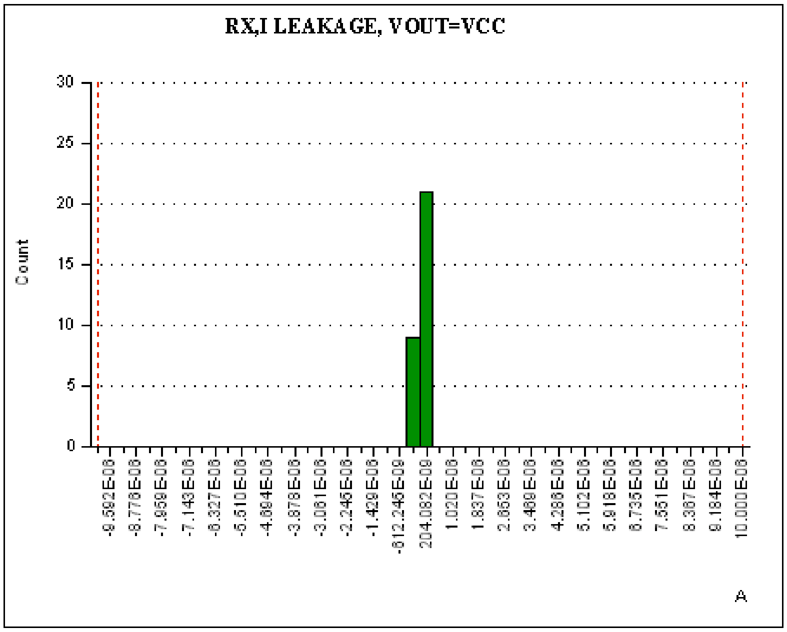
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.006, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

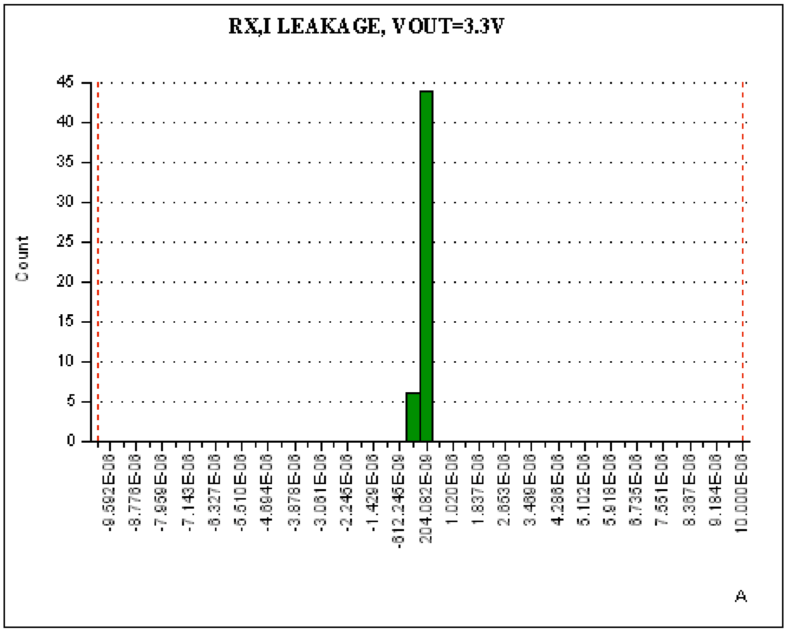
Min	-11.149E-09	**Skew**	-0.3878
Max	15.281E-09	**StatHigh**	N/A
Mean	3.756E-09	**StatLow**	N/A
StdDev	7.844E-09	**NWithinSpec**	30
25%	-3.708E-09	**NOutsideSpec**	0
Mean+3*StdDev	27.289E-09	**90%**	13.021E-09
		Range	26.430E-09
Mean-3*StdDev	-19.778E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.006, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-12.216E-09	**StatLow**	N/A
Max	23.388E-09	**NWithinSpec**	50
Mean	10.971E-09	**NOutsideSpec**	0
StdDev	8.167E-09	**90%**	21.044E-09
25%	7.177E-09	**Range**	35.604E-09
Mean+3*StdDev	35.471E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-13.529E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.6583		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

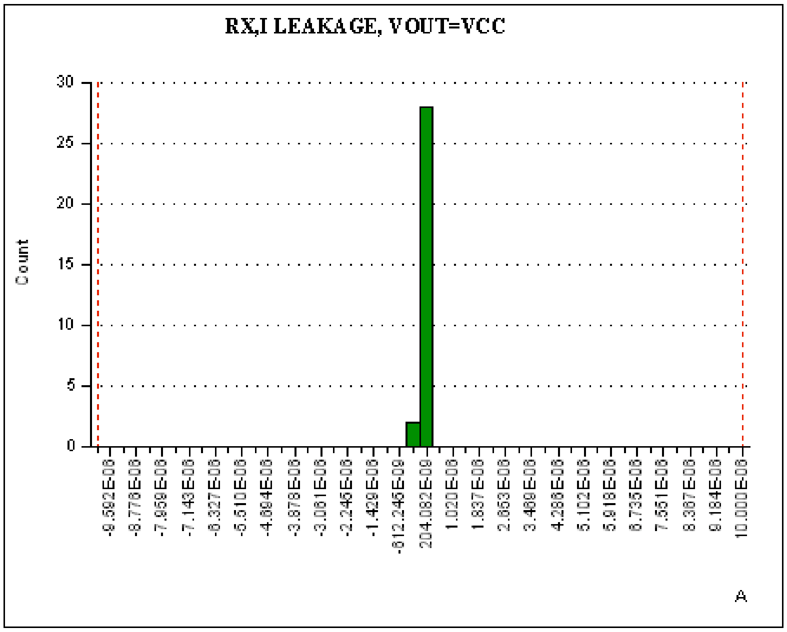
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.007, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

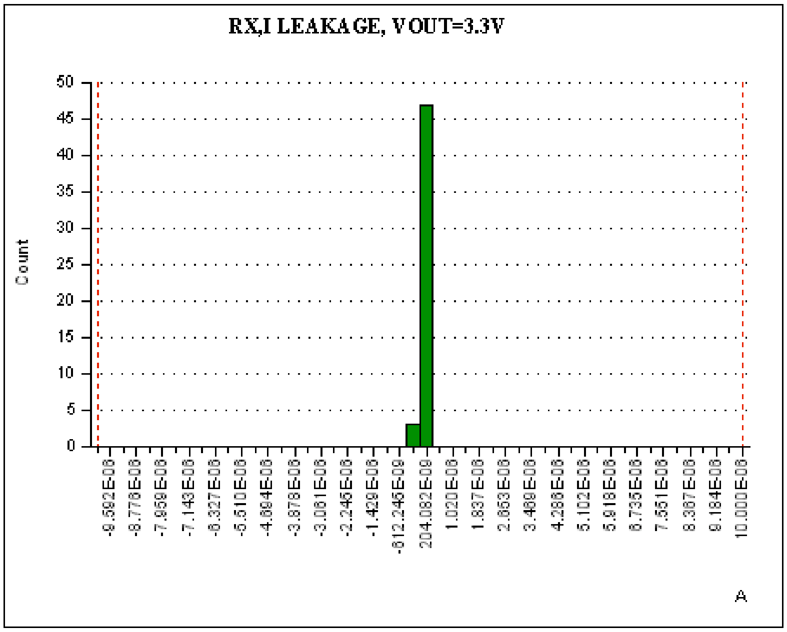
Min	-6.433E-09	**Skew**	-0.5428
Max	15.821E-09	**StatHigh**	N/A
Mean	6.122E-09	**StatLow**	N/A
StdDev	4.423E-09	**NWithinSpec**	30
25%	4.179E-09	**NOutsideSpec**	0
Mean+3*StdDev	19.391E-09	**90%**	11.632E-09
		Range	22.254E-09
Mean-3*StdDev	-7.147E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.007, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-2.722E-09	**StatLow**	N/A
Max	25.572E-09	**NWithinSpec**	50
Mean	11.571E-09	**NOutsideSpec**	0
StdDev	6.079E-09	**90%**	18.907E-09
25%	9.473E-09	**Range**	28.294E-09
Mean+3*StdDev	29.809E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-6.668E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.3993		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

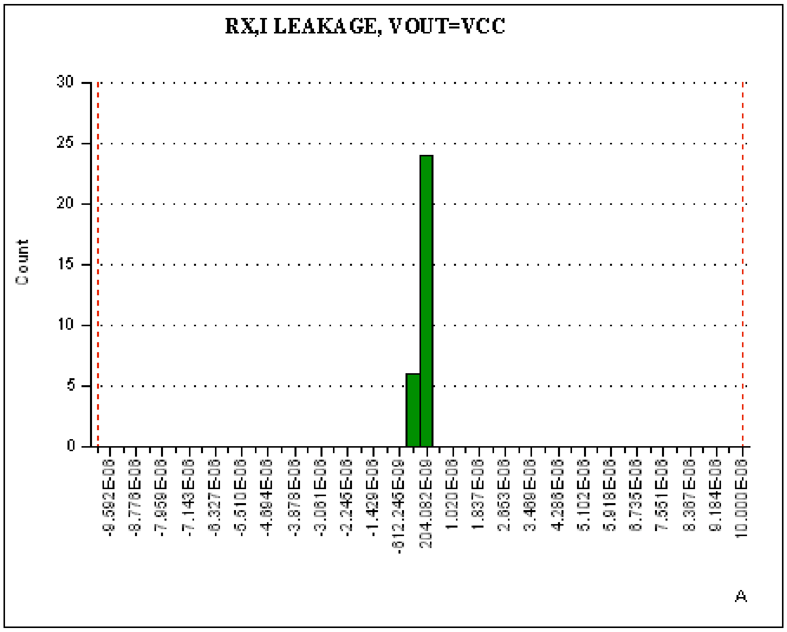
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.008, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

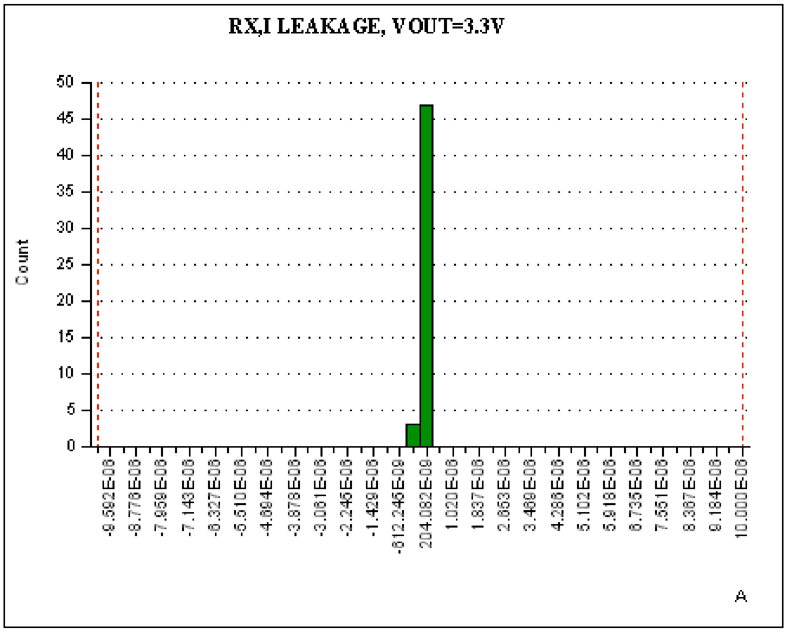
Min	-5.377E-09	**Skew**	-0.5815
Max	13.708E-09	**StatHigh**	N/A
Mean	5.429E-09	**StatLow**	N/A
StdDev	5.402E-09	**NWithinSpec**	30
25%	1.918E-09	**NOutsideSpec**	0
Mean+3*StdDev	21.634E-09	**90%**	11.461E-09
		Range	19.085E-09
Mean-3*StdDev	-10.776E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.008, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-2.659E-09	**StatLow**	N/A
Max	22.764E-09	**NWithinSpec**	50
Mean	11.793E-09	**NOutsideSpec**	0
StdDev	6.116E-09	**90%**	19.371E-09
25%	8.667E-09	**Range**	25.423E-09
Mean+3*StdDev	30.141E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-6.555E-09	**Cpl**	>4.0000
		Cpu	>4.0000
Cpk	>4.0000		
Skew	-0.4695		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

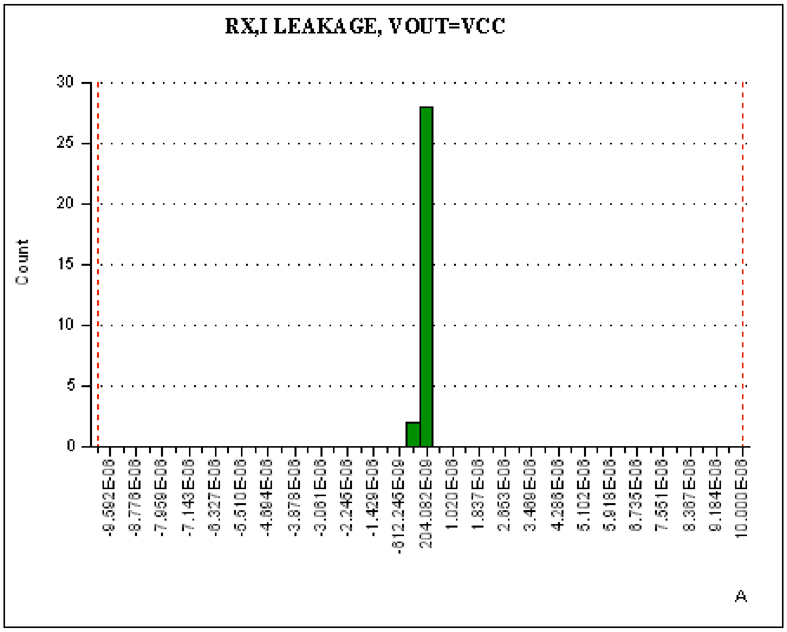
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=11.009, Test.Name=RX,I LEAKAGE, VOUT=VCC



Statistics: (A)

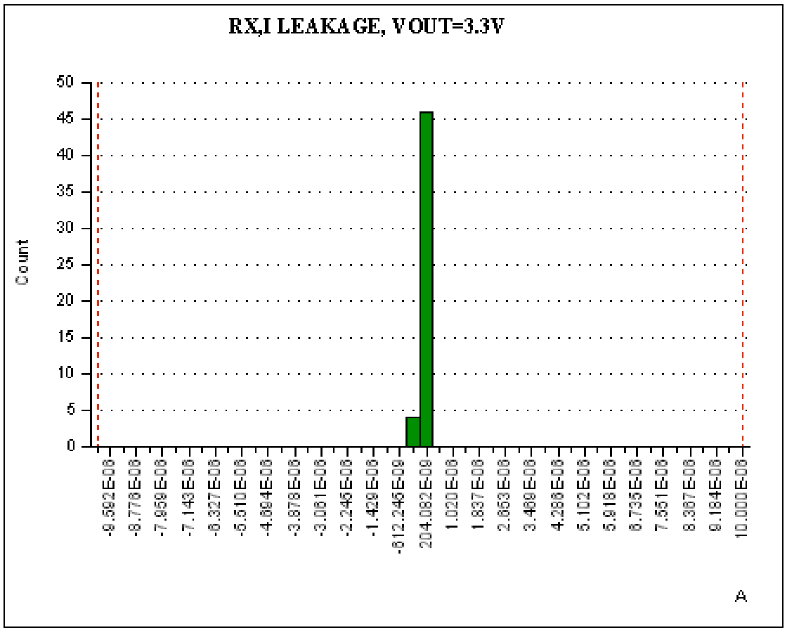
Min	-1.249E-09	**Skew**	-1.2140
Max	15.010E-09	**StatHigh**	N/A
Mean	8.610E-09	**StatLow**	N/A
StdDev	3.658E-09	**NWithinSpec**	30
25%	7.323E-09	**NOutsideSpec**	0
Mean+3*StdDev	19.585E-09	**90%**	12.173E-09
		Range	16.259E-09
Mean-3*StdDev	-2.365E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=11.009, Test.Name=RX,I LEAKAGE, VOUT=3.3V



Statistics: (A)

Min	-4.540E-09	**StatLow**	N/A
Max	28.025E-09	**NWithinSpec**	50
Mean	10.305E-09	**NOutsideSpec**	0
StdDev	7.494E-09	**90%**	20.628E-09
25%	5.408E-09	**Range**	32.565E-09
Mean+3*StdDev	32.787E-09	**NOutsideSpec**	0
		Cp	>4.0000
Mean-3*StdDev	-12.177E-09	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	>4.0000
Skew	0.1207		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

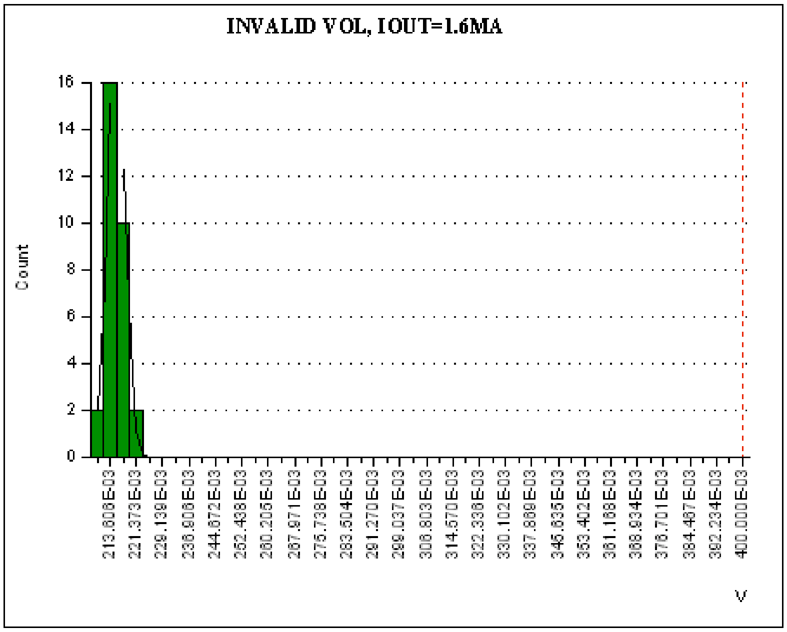
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=12.000, Test.Name=INVALID VOL, IOUT=1.6MA



Statistics: (V)

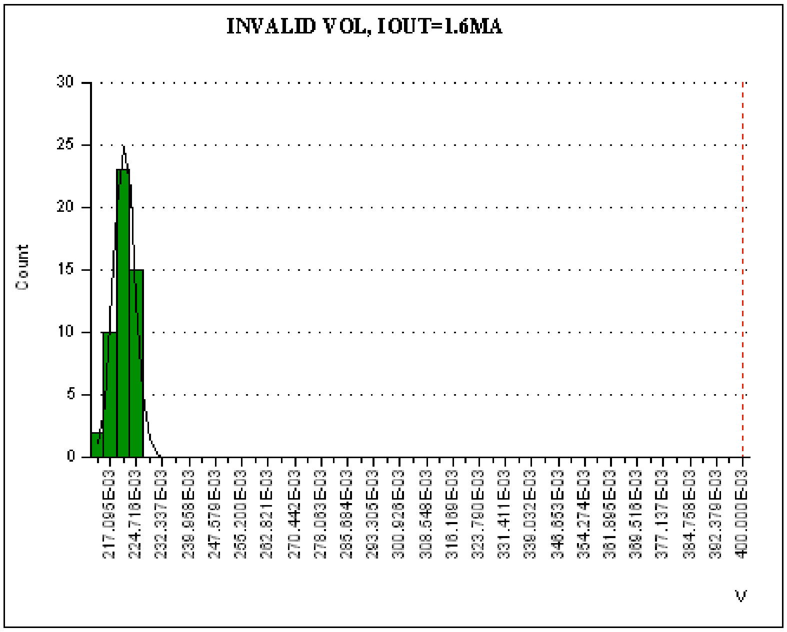
Min	209.723E-03	**Skew**	0.3014
Max	220.851E-03	**StatHigh**	N/A
Mean	215.078E-03	**StatLow**	N/A
StdDev	2.552E-03	**NWithinSpec**	30
25%	213.381E-03	**NOutsideSpec**	0
Mean+3*StdDev	222.734E-03	**90%**	218.756E-03
		Range	11.127E-03
Mean-3*StdDev	207.422E-03	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=12.000, Test.Name=INVALID VOL, IOUT=1.6MA



Statistics: (V)

Min	213.284E-03	**StatLow**	N/A
Max	226.255E-03	**NWithinSpec**	50
Mean	220.916E-03	**NOutsideSpec**	0
StdDev	3.048E-03	**90%**	225.099E-03
25%	219.363E-03	**Range**	12.970E-03
Mean+3*StdDev	230.061E-03	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	211.772E-03	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.1872		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

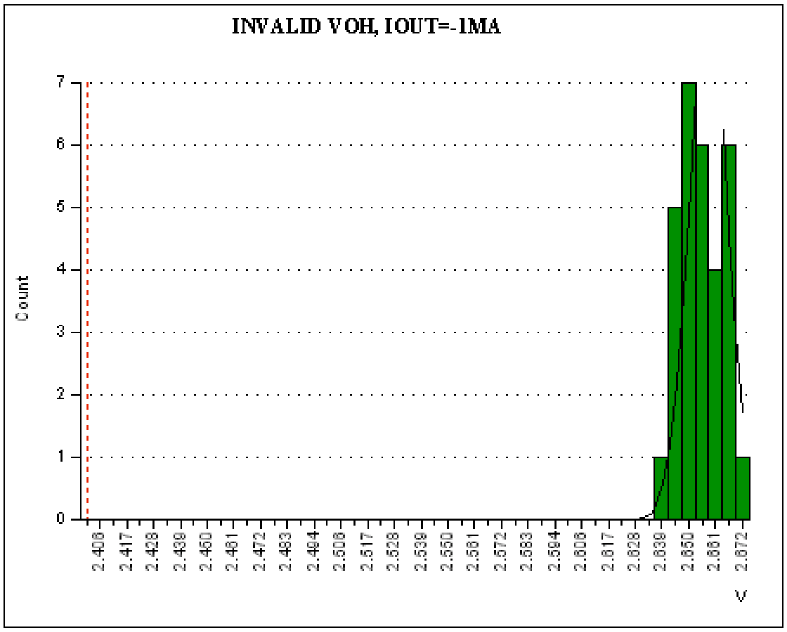
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=12.001, Test.Name=INVALID VOH, IOUT=-1MA



Statistics: (V)

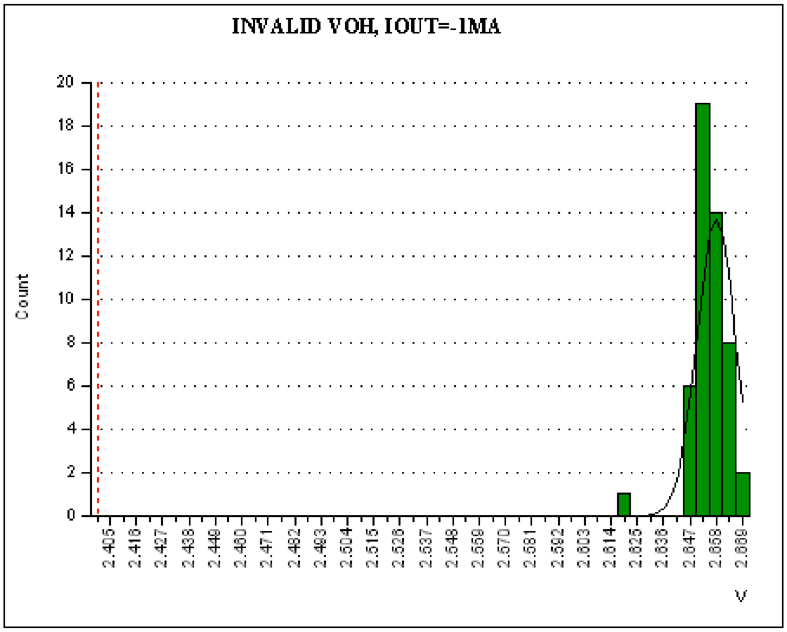
Min	2.641	**Skew**	0.1416
Max	2.672	**StatHigh**	N/A
Mean	2.655	**StatLow**	N/A
StdDev	8.008E-03	**NWithinSpec**	30
25%	2.649	**NOutsideSpec**	0
Mean+3*StdDev	2.679	**90%**	2.665
		Range	31.100E-03
Mean-3*StdDev	2.631	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=12.001, Test.Name=INVALID VOH, IOUT=-1MA



Statistics: (V)

Min	2.617	**StatLow**	N/A
Max	2.669	**NWithinSpec**	50
Mean	2.656	**NOutsideSpec**	0
StdDev	8.001E-03	**90%**	2.664
25%	2.651	**Range**	52.054E-03
Mean+3*StdDev	2.680	**NOutsideSpec**	0
Mean-3*StdDev	2.632	**Cp**	N/A
Cpk	>4.0000	**Cpl**	>4.0000
Skew	-2.0408	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

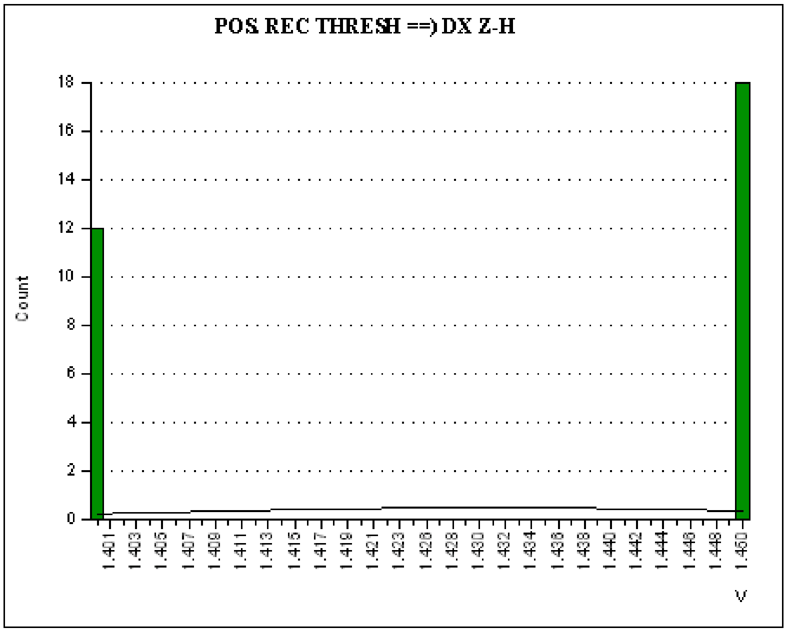
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=13.000, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

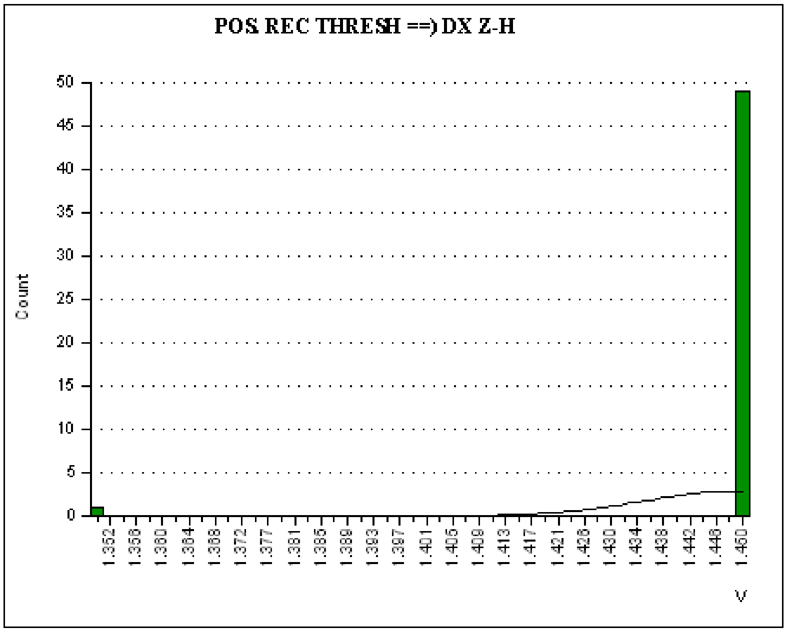
Min	1.400	**Skew**	-0.4301
Max	1.450	**StatHigh**	N/A
Mean	1.430	**StatLow**	N/A
StdDev	24.914E-03	**NWithinSpec**	N/A
25%	1.400	**NOutsideSpec**	N/A
Mean+3*StdDev	1.505	**90%**	1.450
		Range	50.000E-03
Mean-3*StdDev	1.355	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.000, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	1.450	**NWithinSpec**	N/A
Mean	1.448	**NOutsideSpec**	N/A
StdDev	14.142E-03	**90%**	1.450
25%	1.450	**Range**	99.999E-03
Mean+3*StdDev	1.490	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.406	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-7.0711		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

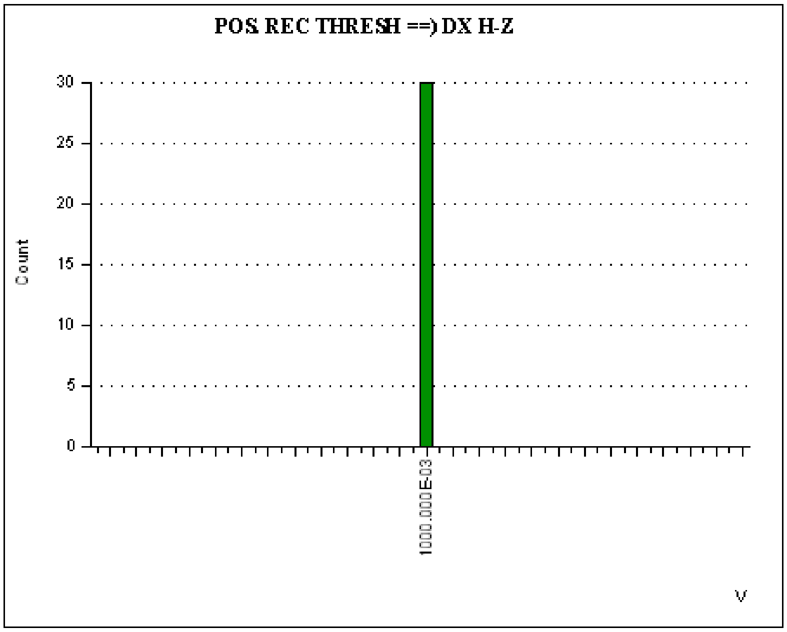
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=13.001, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

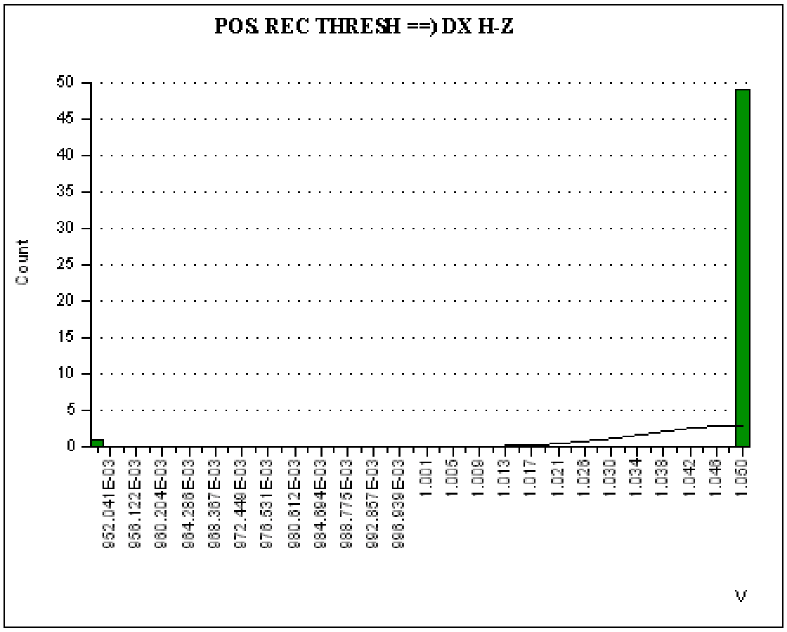
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	1000.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.001, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	950.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	N/A
Mean	1.048	**NOutsideSpec**	N/A
StdDev	14.142E-03	**90%**	1.050
25%	1.050	**Range**	100.000E-03
Mean+3*StdDev	1.090	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.006	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-7.0711		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

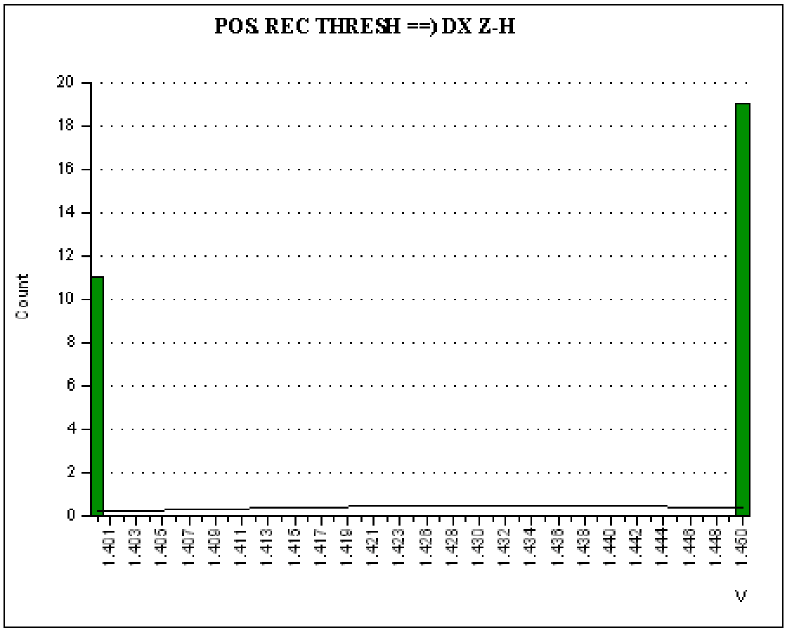
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=13.002, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

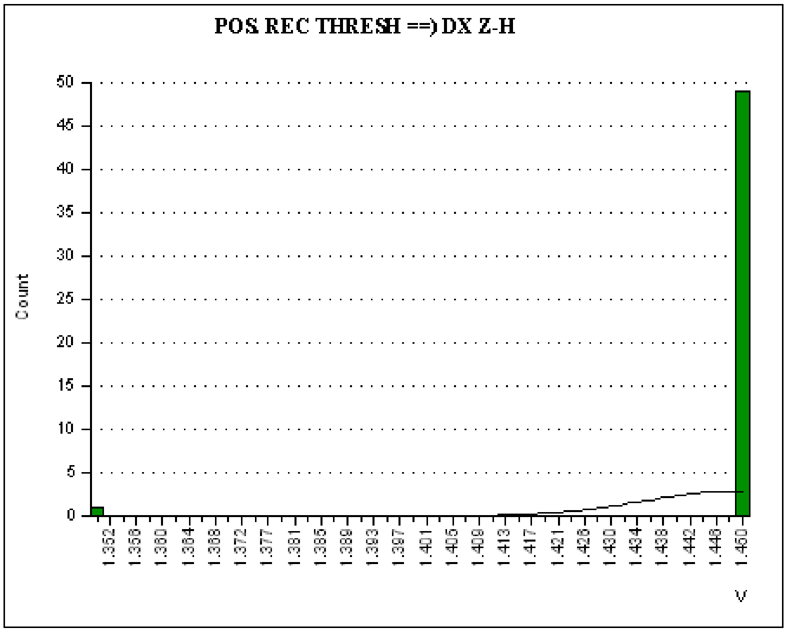
Min	1.400	**Skew**	-0.5829
Max	1.450	**StatHigh**	N/A
Mean	1.432	**StatLow**	N/A
StdDev	24.507E-03	**NWithinSpec**	N/A
25%	1.400	**NOutsideSpec**	N/A
Mean+3*StdDev	1.505	**90%**	1.450
		Range	50.000E-03
Mean-3*StdDev	1.358	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.002, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	1.450	**NWithinSpec**	N/A
Mean	1.448	**NOutsideSpec**	N/A
StdDev	14.142E-03	**90%**	1.450
25%	1.450	**Range**	99.999E-03
Mean+3*StdDev	1.490	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.406	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-7.0711		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

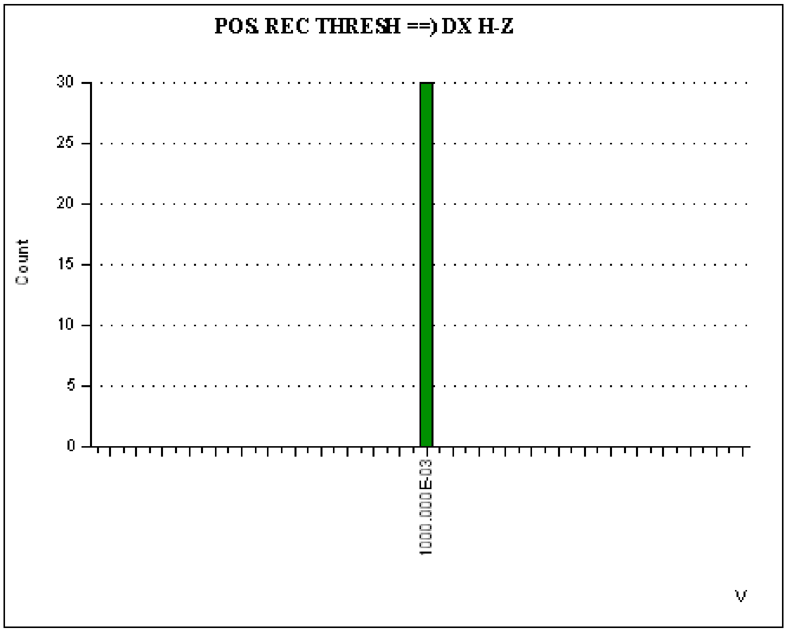
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=13.003, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

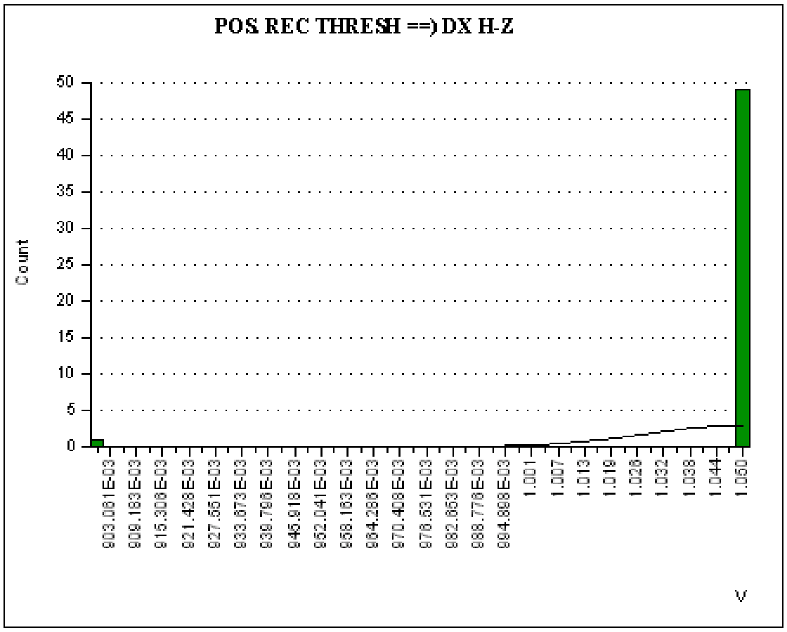
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	1000.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.003, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	N/A
Mean	1.047	**NOutsideSpec**	N/A
StdDev	21.213E-03	**90%**	1.050
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.111	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	983.360E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-7.0711		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

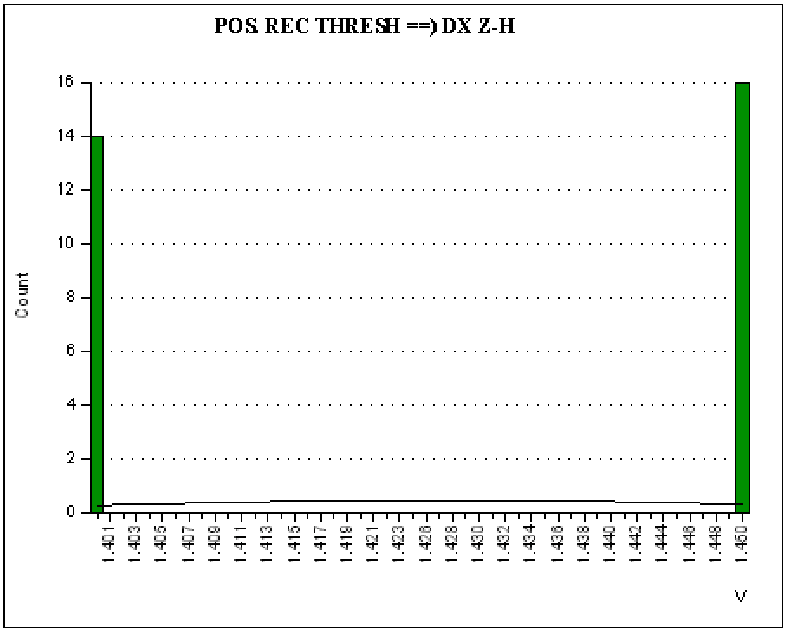
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=13.004, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

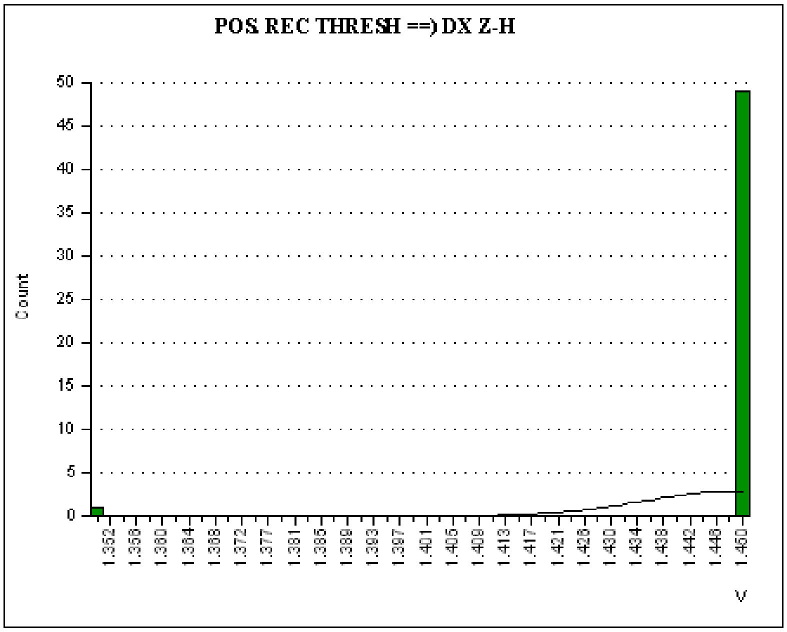
Min	1.400	**Skew**	-0.1408
Max	1.450	**StatHigh**	N/A
Mean	1.427	**StatLow**	N/A
StdDev	25.371E-03	**NWithinSpec**	N/A
25%	1.400	**NOutsideSpec**	N/A
Mean+3*StdDev	1.503	**90%**	1.450
		Range	50.000E-03
Mean-3*StdDev	1.351	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.004, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	1.450	**NWithinSpec**	N/A
Mean	1.448	**NOutsideSpec**	N/A
StdDev	14.142E-03	**90%**	1.450
25%	1.450	**Range**	99.999E-03
Mean+3*StdDev	1.490	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.406	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-7.0711		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

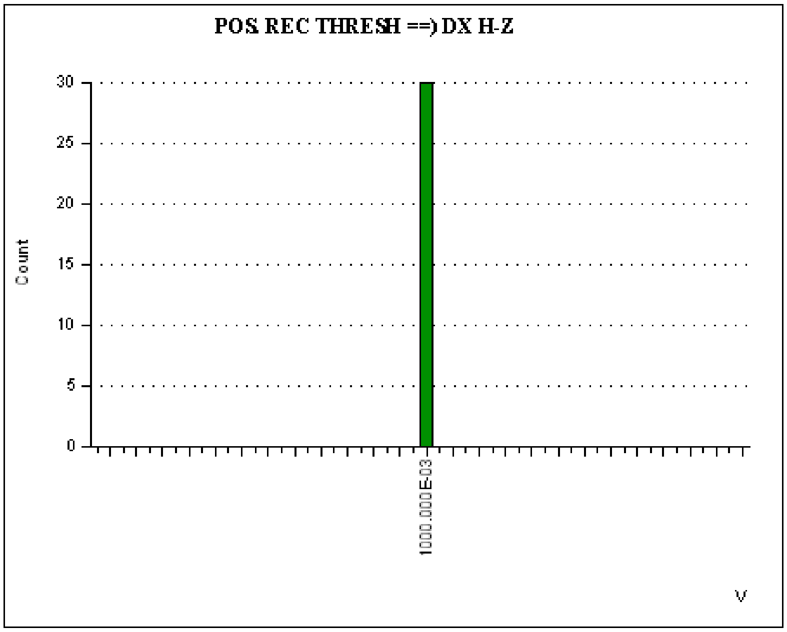
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=13.005, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

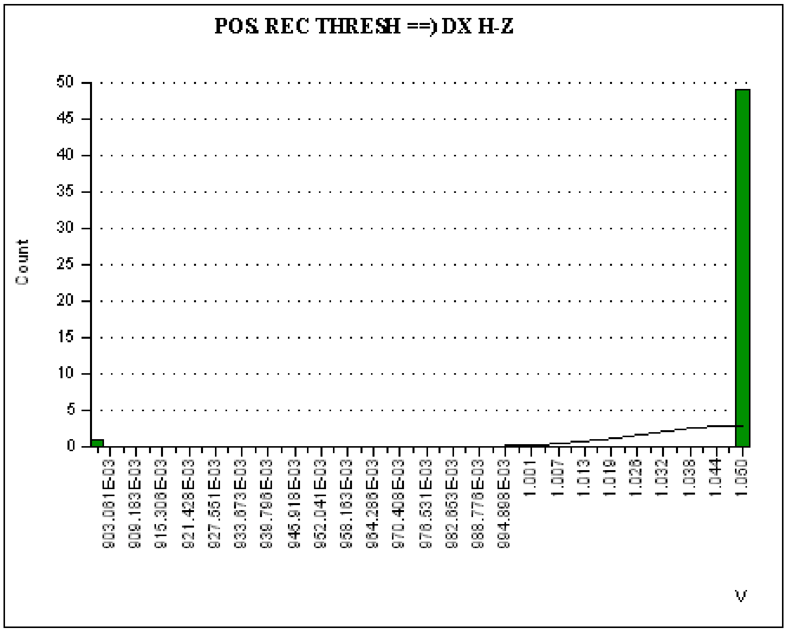
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	1000.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.005, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	N/A
Mean	1.047	**NOutsideSpec**	N/A
StdDev	21.213E-03	**90%**	1.050
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.111	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	983.360E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-7.0711		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

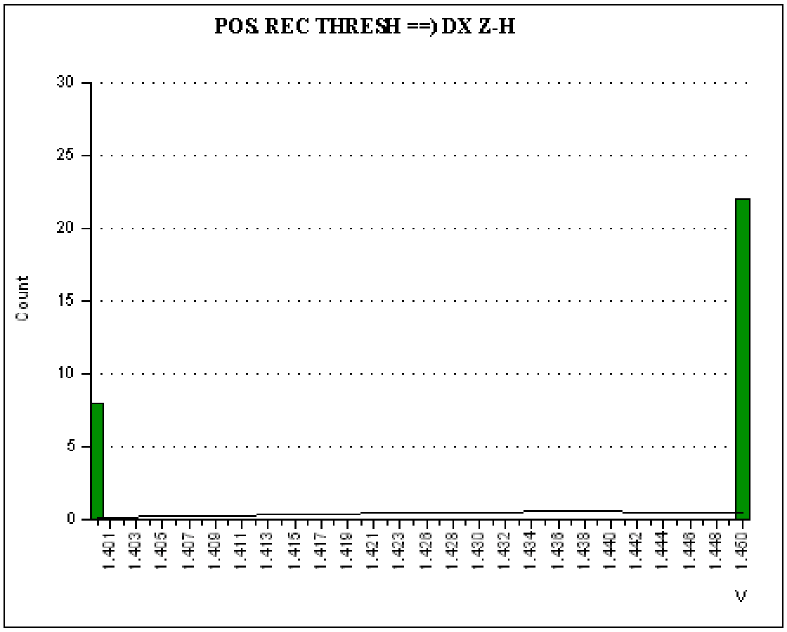
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=13.006, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

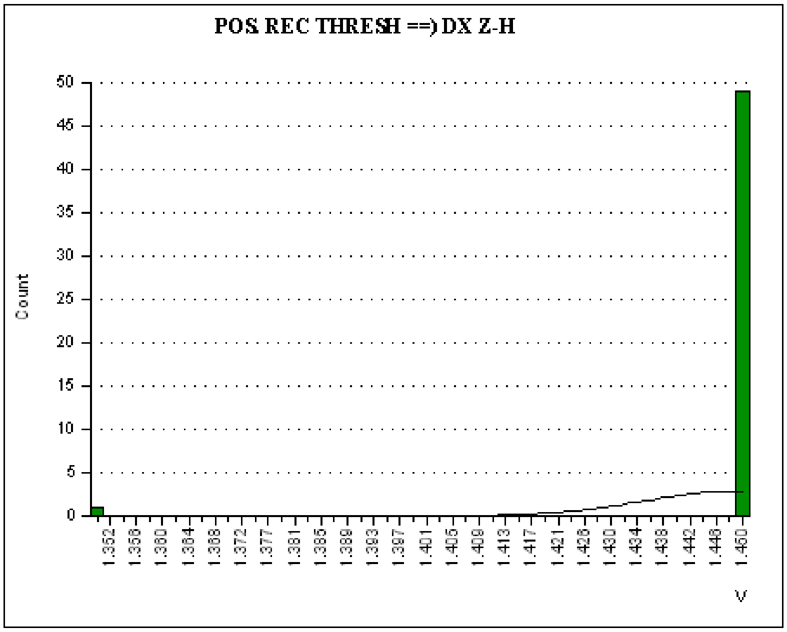
Min	1.400	**Skew**	-1.1117
Max	1.450	**StatHigh**	N/A
Mean	1.437	**StatLow**	N/A
StdDev	22.489E-03	**NWithinSpec**	N/A
25%	1.400	**NOutsideSpec**	N/A
Mean+3*StdDev	1.504	**90%**	1.450
		Range	50.000E-03
Mean-3*StdDev	1.369	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.006, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	1.450	**NWithinSpec**	N/A
Mean	1.448	**NOutsideSpec**	N/A
StdDev	14.142E-03	**90%**	1.450
25%	1.450	**Range**	99.999E-03
Mean+3*StdDev	1.490	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.406	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-7.0711		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

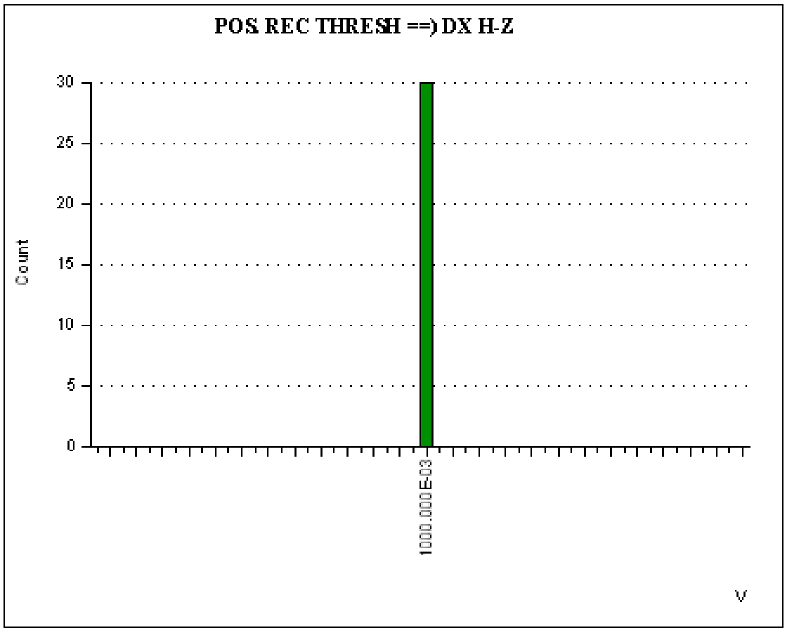
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:11 PM

Test.Number=13.007, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

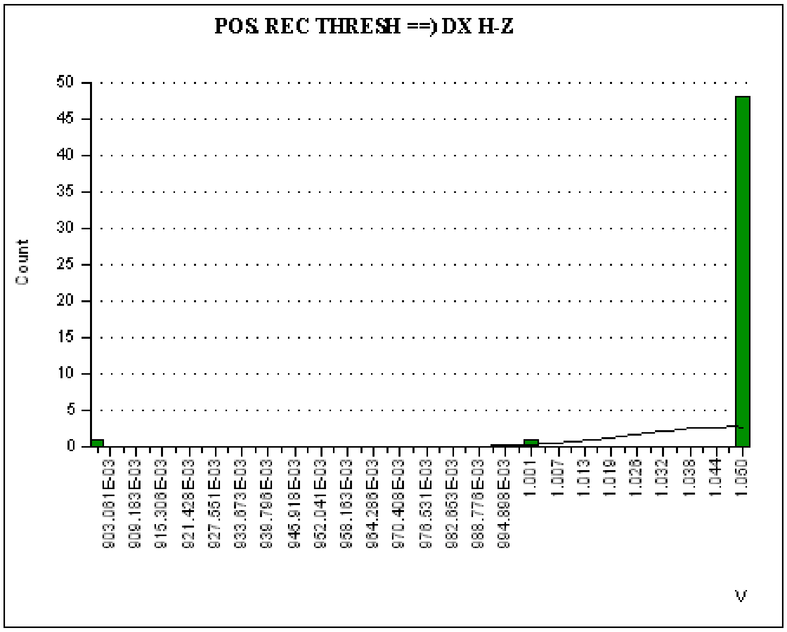
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	1000.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.007, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.050	**NWithinSpec**	N/A
Mean	1.046	**NOutsideSpec**	N/A
StdDev	22.223E-03	**90%**	1.050
25%	1.050	**Range**	150.000E-03
Mean+3*StdDev	1.113	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	979.330E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-6.2104		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

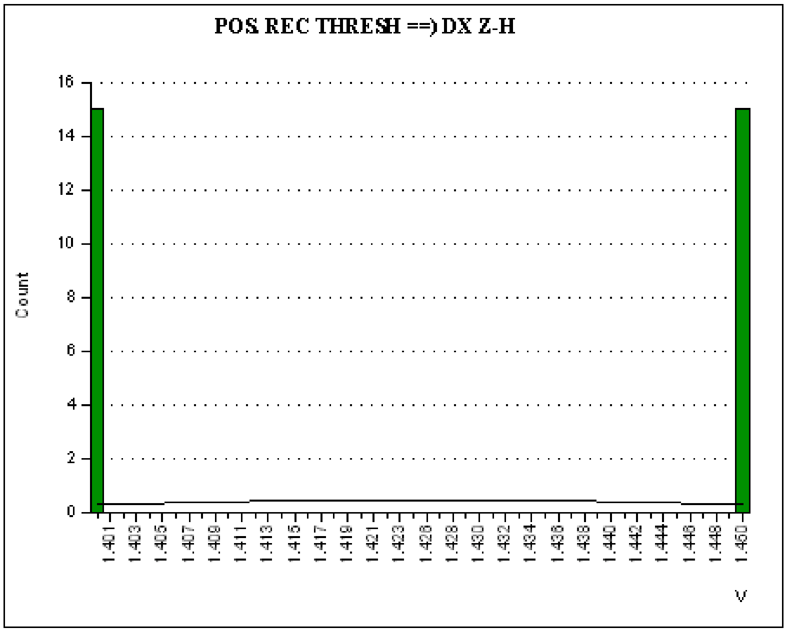
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.008, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

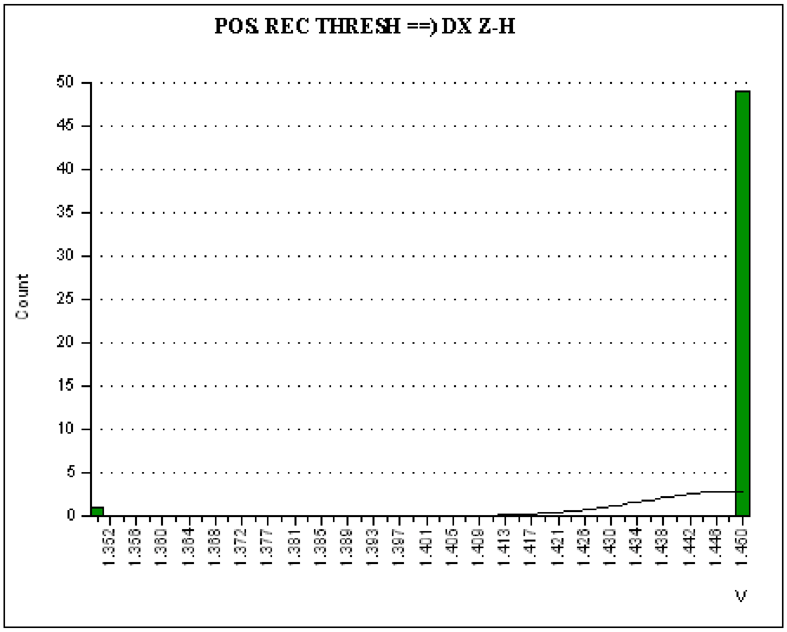
Min	1.400	**Skew**	0.0000
Max	1.450	**StatHigh**	N/A
Mean	1.425	**StatLow**	N/A
StdDev	25.427E-03	**NWithinSpec**	N/A
25%	1.400	**NOutsideSpec**	N/A
Mean+3*StdDev	1.501	**90%**	1.450
		Range	50.000E-03
Mean-3*StdDev	1.349	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.008, Test.Name=POS. REC THRESH ==) DX Z-H



Statistics: (V)

Min	1.350	**StatLow**	N/A
Max	1.450	**NWithinSpec**	N/A
Mean	1.448	**NOutsideSpec**	N/A
StdDev	14.142E-03	**90%**	1.450
25%	1.450	**Range**	99.999E-03
Mean+3*StdDev	1.490	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.406	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-7.0711		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

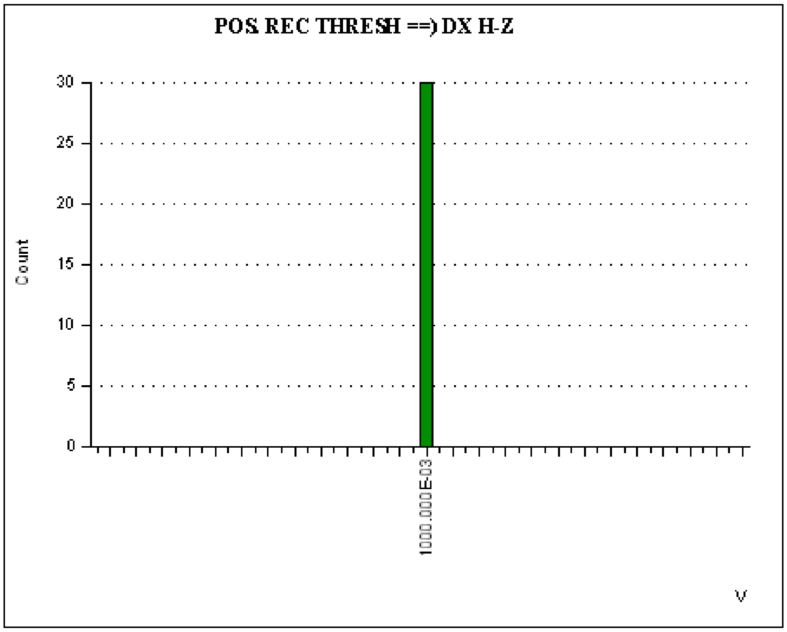
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.009, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

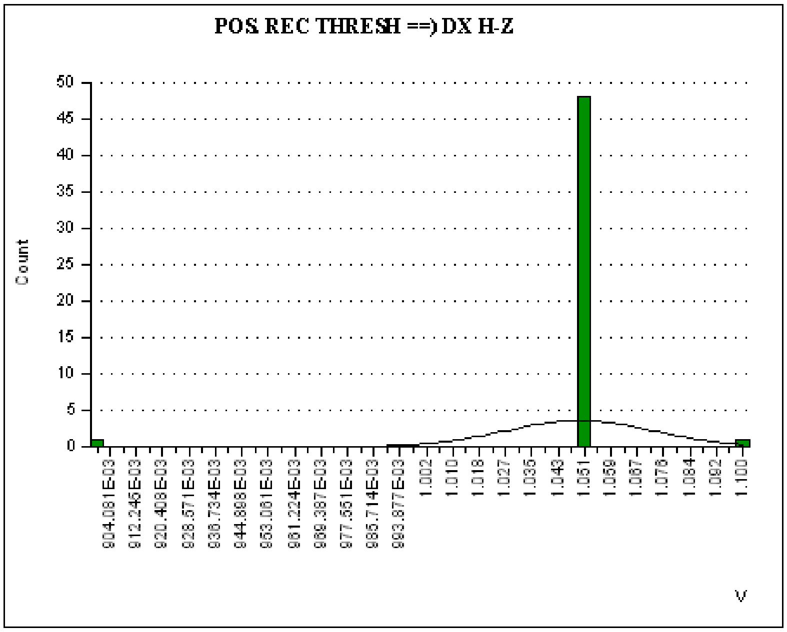
Min	1000.000E-03	**Skew**	N/A
Max	1000.000E-03	**StatHigh**	N/A
Mean	1000.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	1000.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	1000.000E-03	**90%**	1000.000E-03
		Range	0
Mean-3*StdDev	1000.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.009, Test.Name=POS. REC THRESH ==) DX H-Z



Statistics: (V)

Min	900.000E-03	**StatLow**	N/A
Max	1.100	**NWithinSpec**	N/A
Mean	1.048	**NOutsideSpec**	N/A
StdDev	22.497E-03	**90%**	1.050
25%	1.050	**Range**	200.000E-03
Mean+3*StdDev	1.115	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	980.509E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-5.7893		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

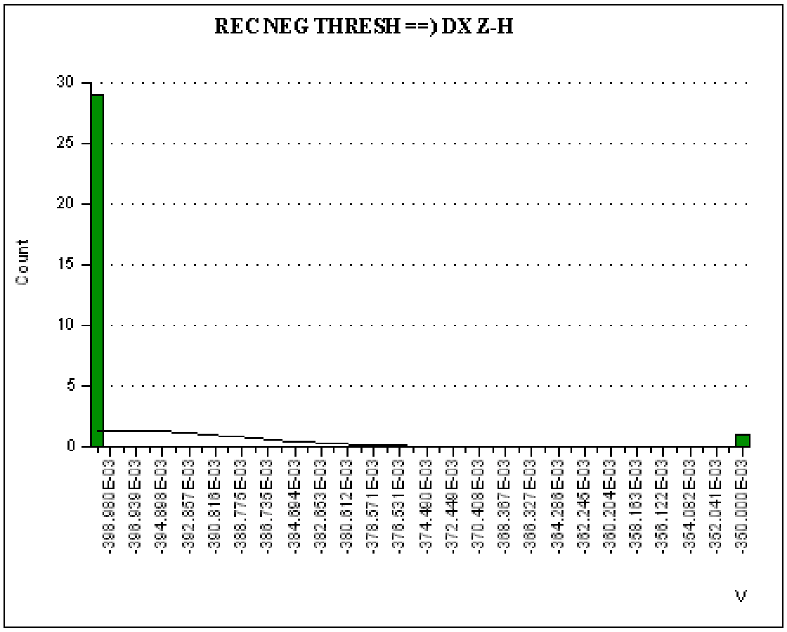
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.010, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

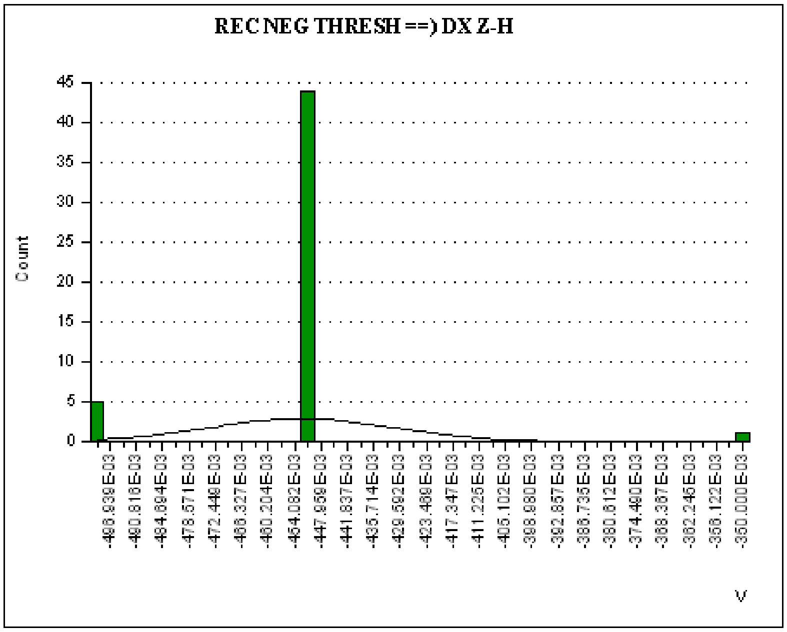
Min	-400.000E-03	**Skew**	5.4772
Max	-350.000E-03	**StatHigh**	N/A
Mean	-398.333E-03	**StatLow**	N/A
StdDev	9.129E-03	**NWithinSpec**	N/A
25%	-400.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-370.947E-03	**90%**	-400.000E-03
		Range	50.000E-03
Mean-3*StdDev	-425.719E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.010, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-453.000E-03	**NOutsideSpec**	N/A
StdDev	21.213E-03	**90%**	-450.000E-03
25%	-450.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-389.360E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-516.640E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.2801		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

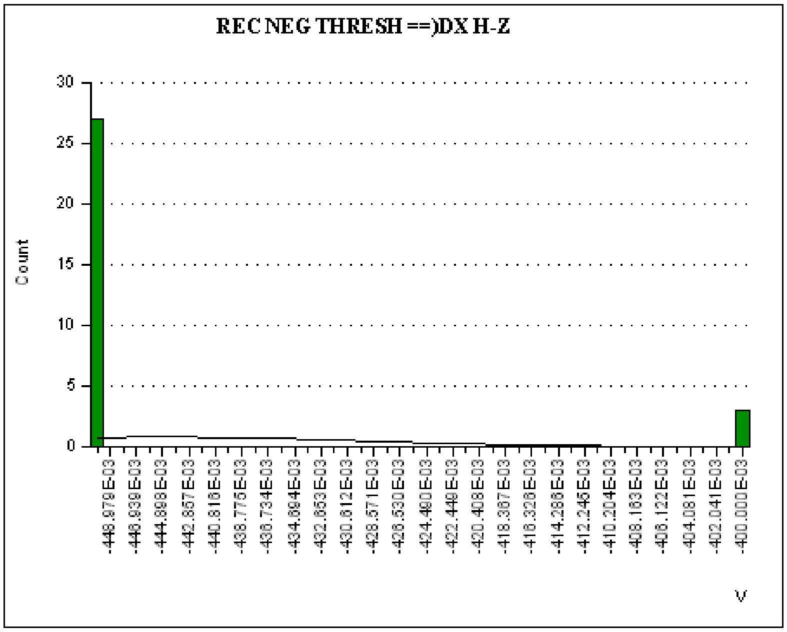
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.011, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

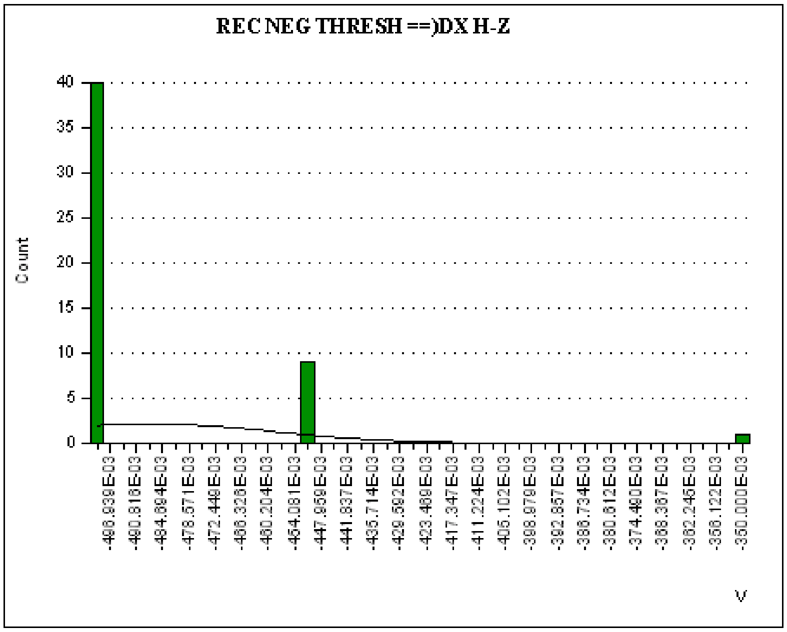
Min	-450.000E-03	**Skew**	2.8091
Max	-400.000E-03	**StatHigh**	N/A
Mean	-445.000E-03	**StatLow**	N/A
StdDev	15.256E-03	**NWithinSpec**	N/A
25%	-450.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-399.231E-03	**90%**	-425.000E-03
		Range	50.000E-03
Mean-3*StdDev	-490.769E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.011, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-488.000E-03	**NOutsideSpec**	N/A
StdDev	27.775E-03	**90%**	-450.000E-03
25%	-500.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-404.676E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-571.324E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.0289		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

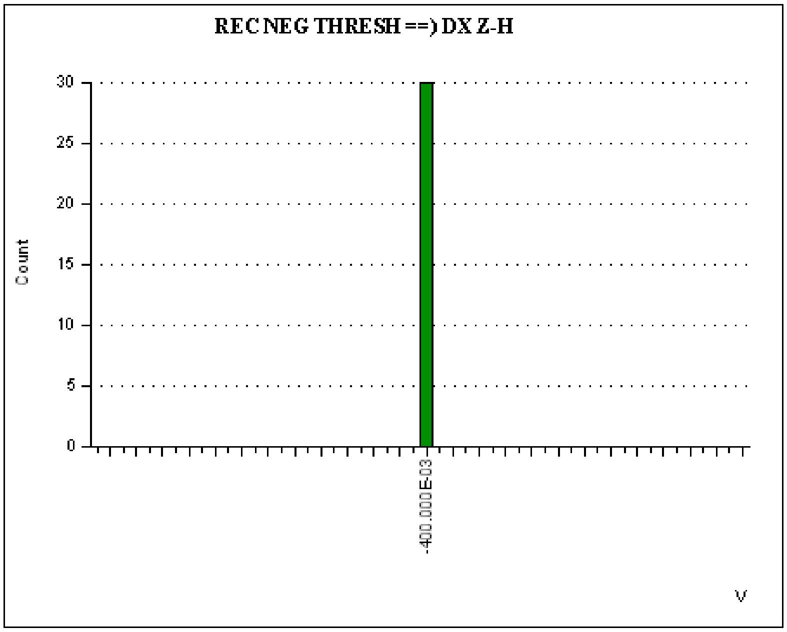
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.012, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

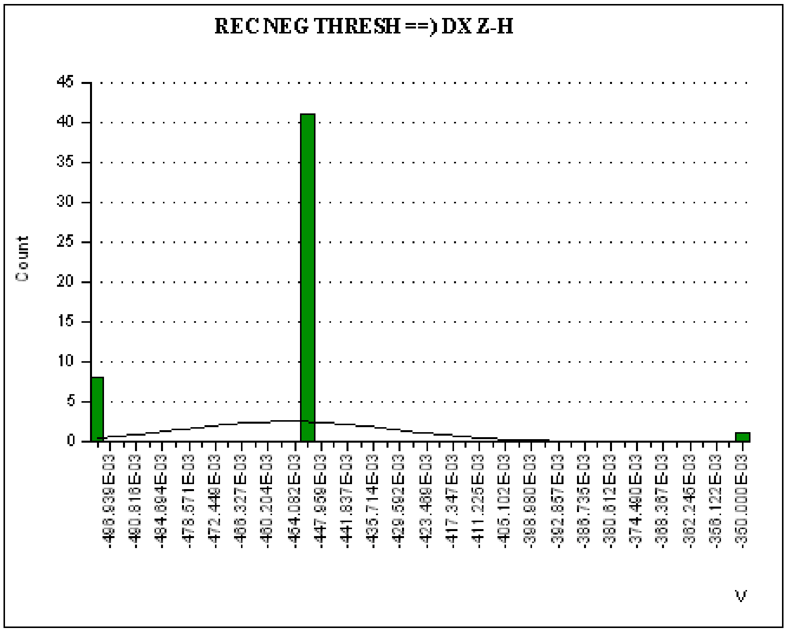
Min	-400.000E-03	**Skew**	N/A
Max	-400.000E-03	**StatHigh**	N/A
Mean	-400.000E-03	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	-400.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-400.000E-03	**90%**	-400.000E-03
		Range	0
Mean-3*StdDev	-400.000E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.012, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-456.000E-03	**NOutsideSpec**	N/A
StdDev	23.990E-03	**90%**	-450.000E-03
25%	-450.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-384.031E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-527.969E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.7982		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

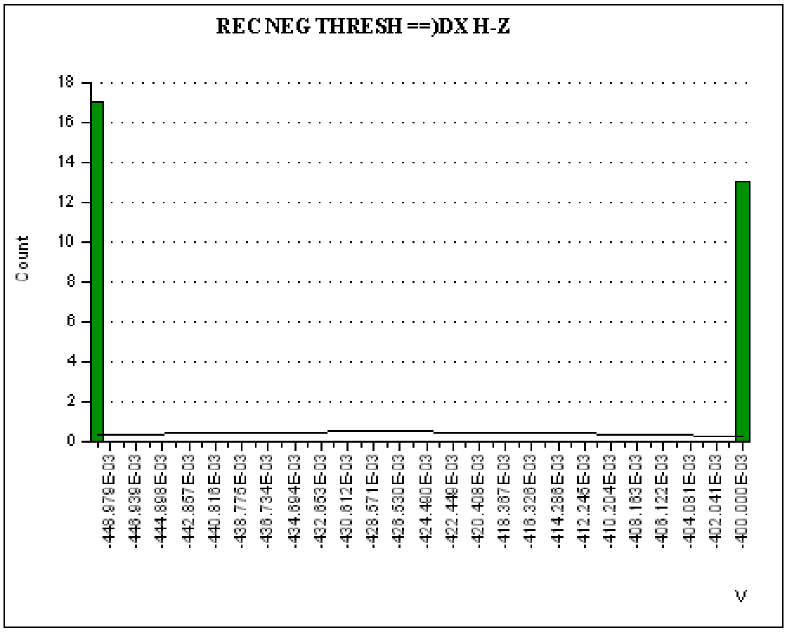
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.013, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

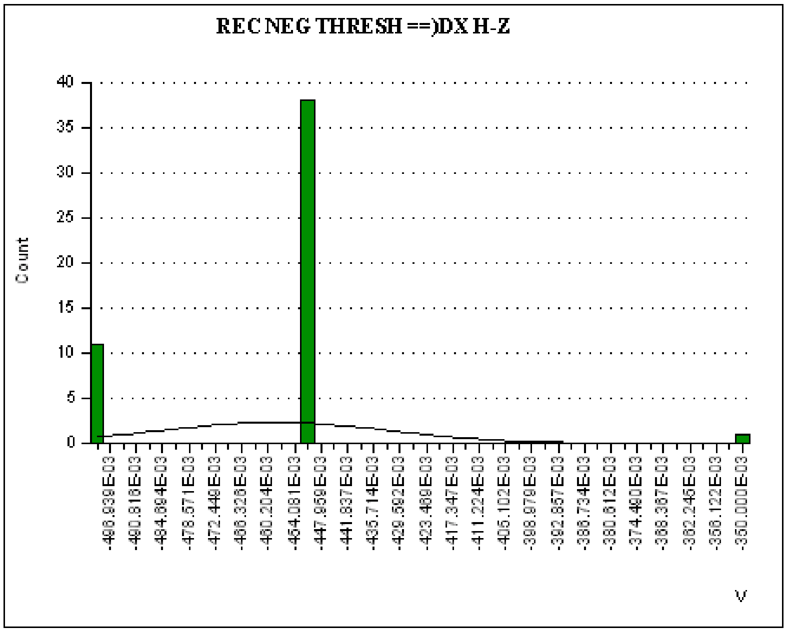
Min	-450.000E-03	**Skew**	0.2834
Max	-400.000E-03	**StatHigh**	N/A
Mean	-428.333E-03	**StatLow**	N/A
StdDev	25.200E-03	**NWithinSpec**	N/A
25%	-450.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-352.732E-03	**90%**	-400.000E-03
		Range	50.000E-03
Mean-3*StdDev	-503.934E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.013, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-459.000E-03	**NOutsideSpec**	N/A
StdDev	26.128E-03	**90%**	-450.000E-03
25%	-450.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-380.617E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-537.383E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.6729		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

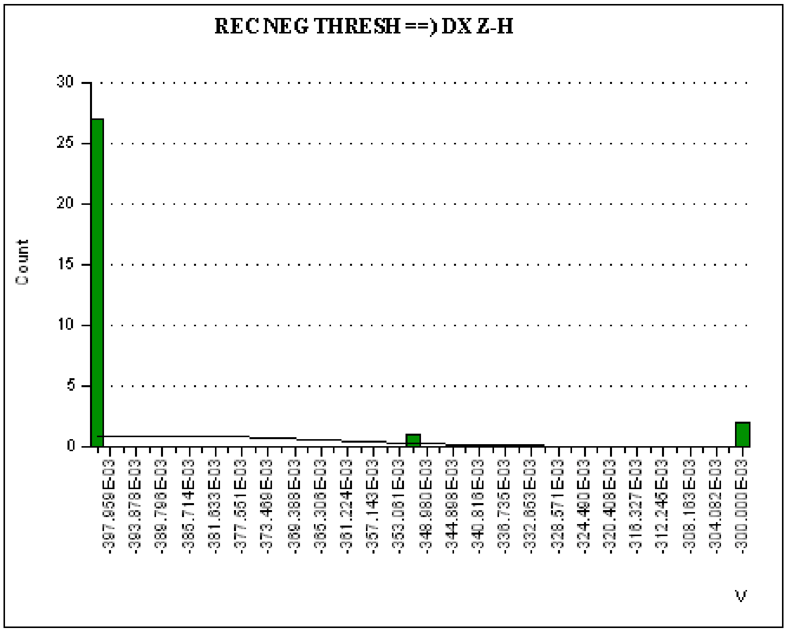
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.014, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

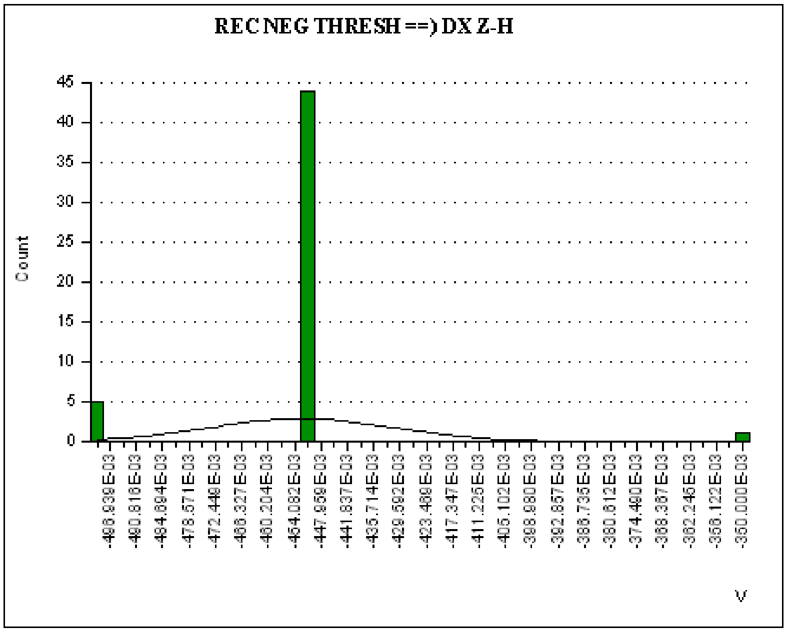
Min	-400.000E-03	**Skew**	3.1590
Max	-300.000E-03	**StatHigh**	N/A
Mean	-391.667E-03	**StatLow**	N/A
StdDev	26.533E-03	**NWithinSpec**	N/A
25%	-400.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-312.066E-03	**90%**	-375.000E-03
		Range	100.000E-03
Mean-3*StdDev	-471.267E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.014, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-453.000E-03	**NOutsideSpec**	N/A
StdDev	21.213E-03	**90%**	-450.000E-03
25%	-450.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-389.360E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-516.640E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.2801		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

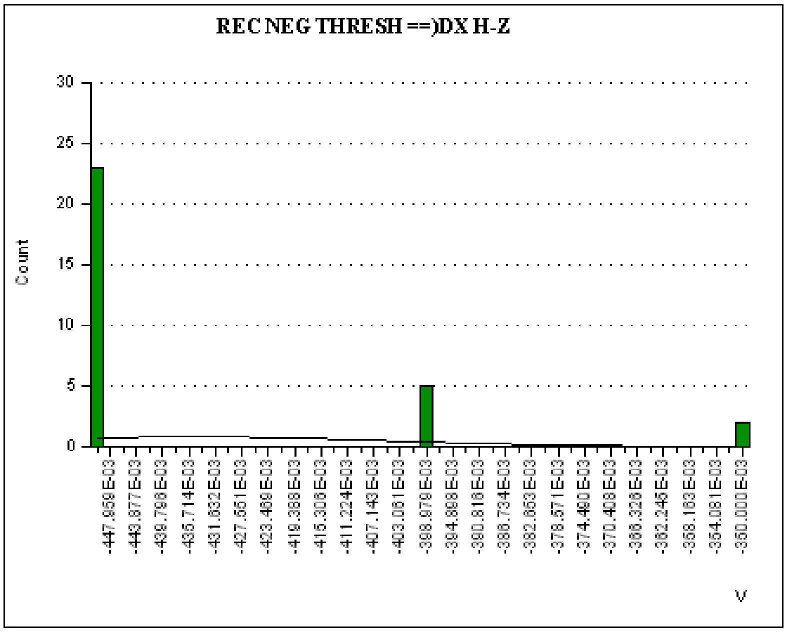
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.015, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

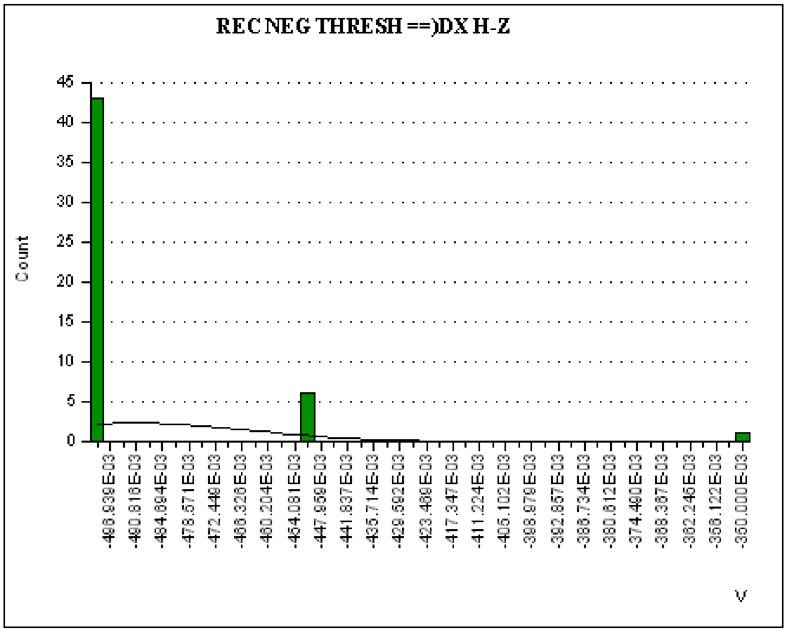
Min	-450.000E-03	**Skew**	1.9060
Max	-350.000E-03	**StatHigh**	N/A
Mean	-435.000E-03	**StatLow**	N/A
StdDev	29.798E-03	**NWithinSpec**	N/A
25%	-450.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-345.605E-03	**90%**	-400.000E-03
		Range	100.000E-03
Mean-3*StdDev	-524.394E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.015, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-491.000E-03	**NOutsideSpec**	N/A
StdDev	26.128E-03	**90%**	-450.000E-03
25%	-500.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-412.617E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-569.383E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.7966		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

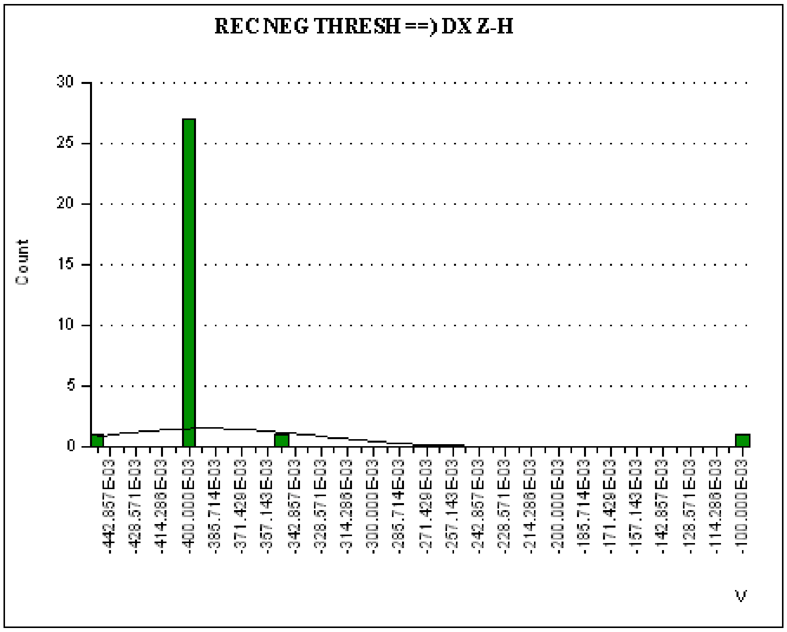
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.016, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

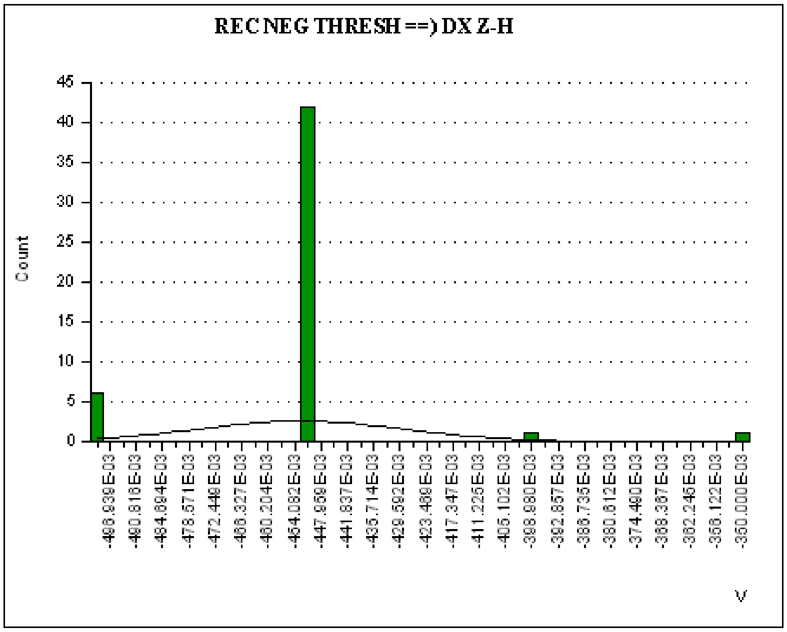
Min	-450.000E-03	**Skew**	5.0058
Max	-100.000E-03	**StatHigh**	N/A
Mean	-390.000E-03	**StatLow**	N/A
StdDev	56.324E-03	**NWithinSpec**	N/A
25%	-400.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-221.027E-03	**90%**	-400.000E-03
		Range	350.000E-03
Mean-3*StdDev	-558.973E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.016, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-453.000E-03	**NOutsideSpec**	N/A
StdDev	23.496E-03	**90%**	-450.000E-03
25%	-450.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-382.513E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-523.487E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.0158		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

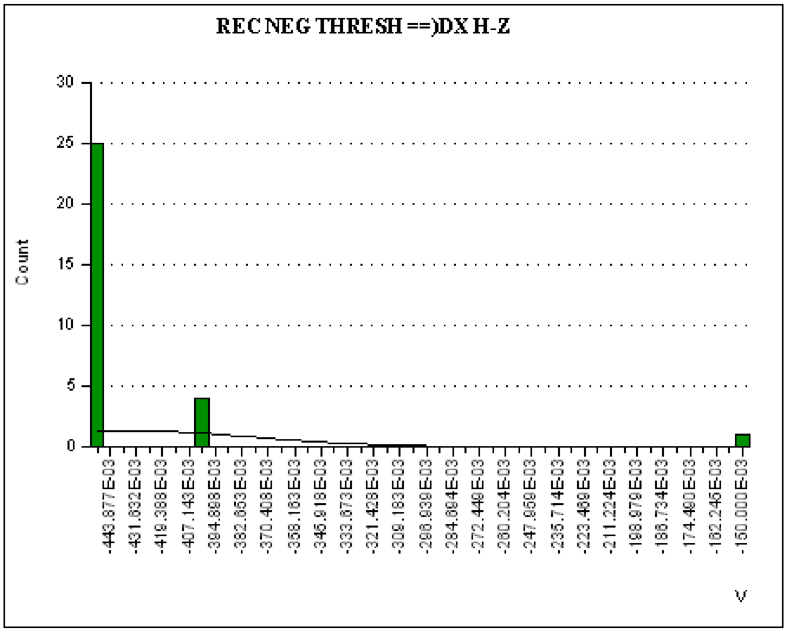
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.017, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

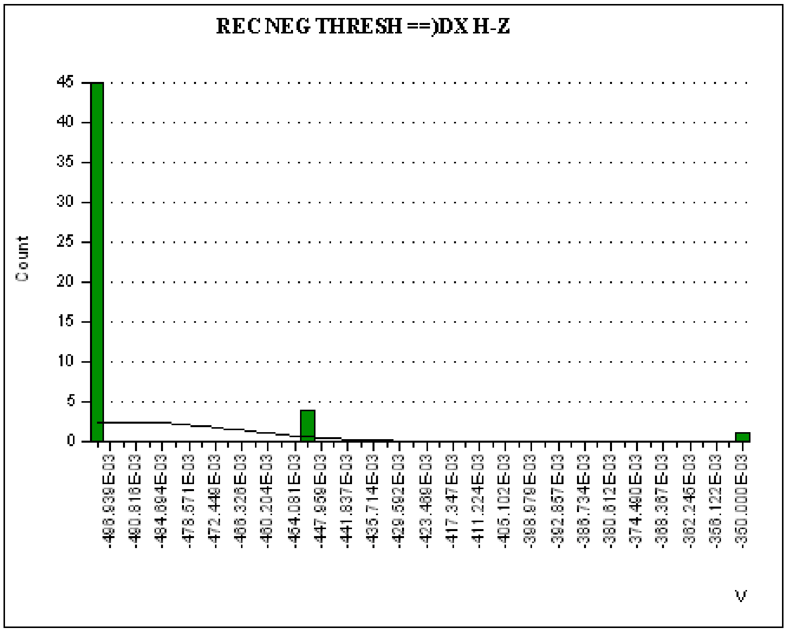
Min	-450.000E-03	**Skew**	4.7354
Max	-150.000E-03	**StatHigh**	N/A
Mean	-433.333E-03	**StatLow**	N/A
StdDev	56.222E-03	**NWithinSpec**	N/A
25%	-450.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-264.667E-03	**90%**	-400.000E-03
		Range	300.000E-03
Mean-3*StdDev	-601.999E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.017, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-493.000E-03	**NOutsideSpec**	N/A
StdDev	24.764E-03	**90%**	-475.000E-03
25%	-500.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-418.707E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-567.292E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	4.5168		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

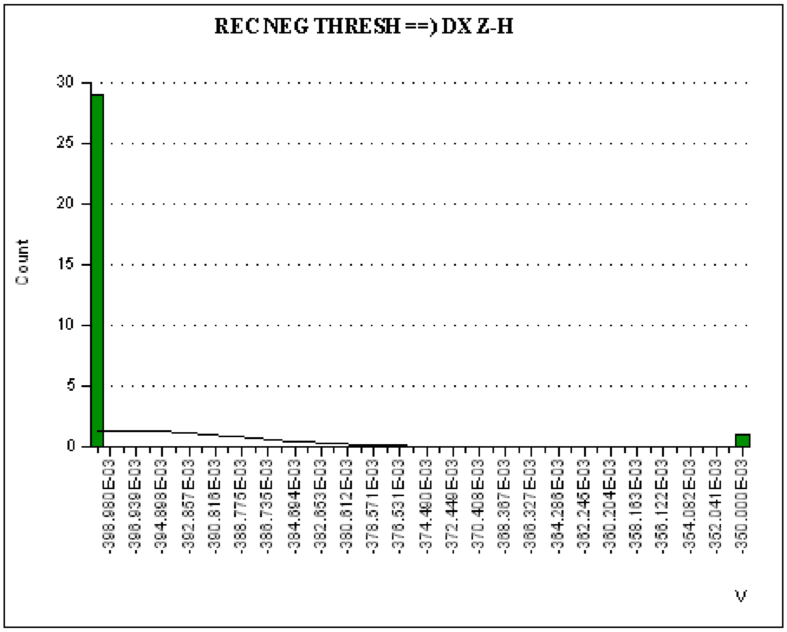
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.018, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

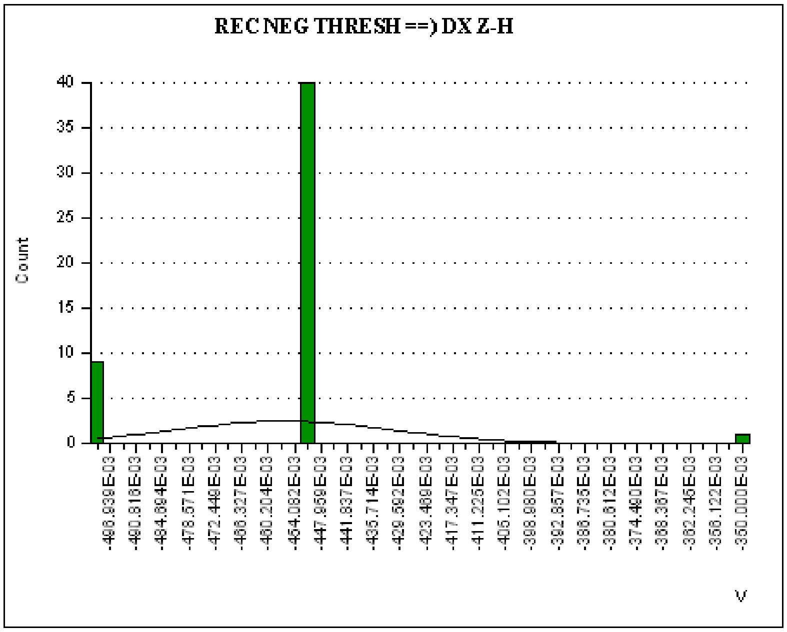
Min	-400.000E-03	**Skew**	5.4772
Max	-350.000E-03	**StatHigh**	N/A
Mean	-398.333E-03	**StatLow**	N/A
StdDev	9.129E-03	**NWithinSpec**	N/A
25%	-400.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-370.947E-03	**90%**	-400.000E-03
		Range	50.000E-03
Mean-3*StdDev	-425.719E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.018, Test.Name=REC NEG THRESH ==) DX Z-H



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-457.000E-03	**NOutsideSpec**	N/A
StdDev	24.764E-03	**90%**	-450.000E-03
25%	-450.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-382.707E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-531.293E-03	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.7324		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

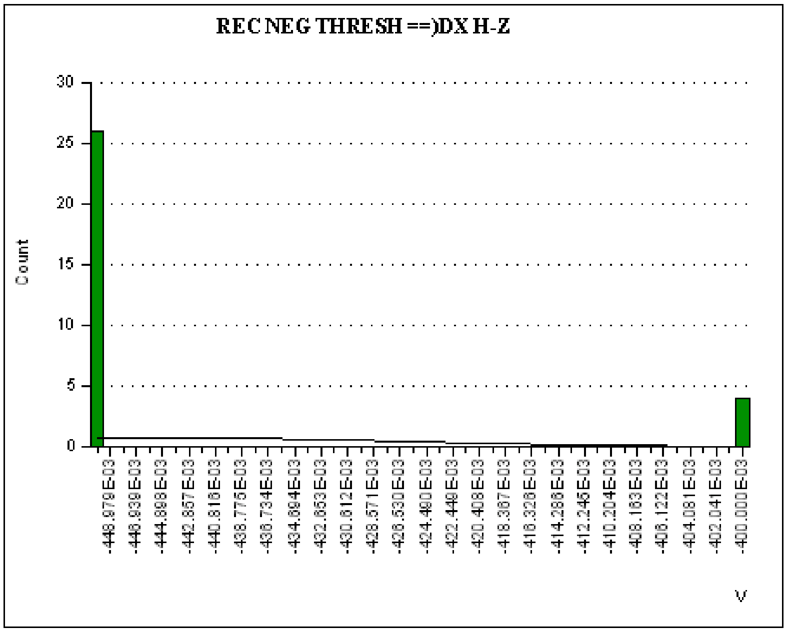
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=13.019, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

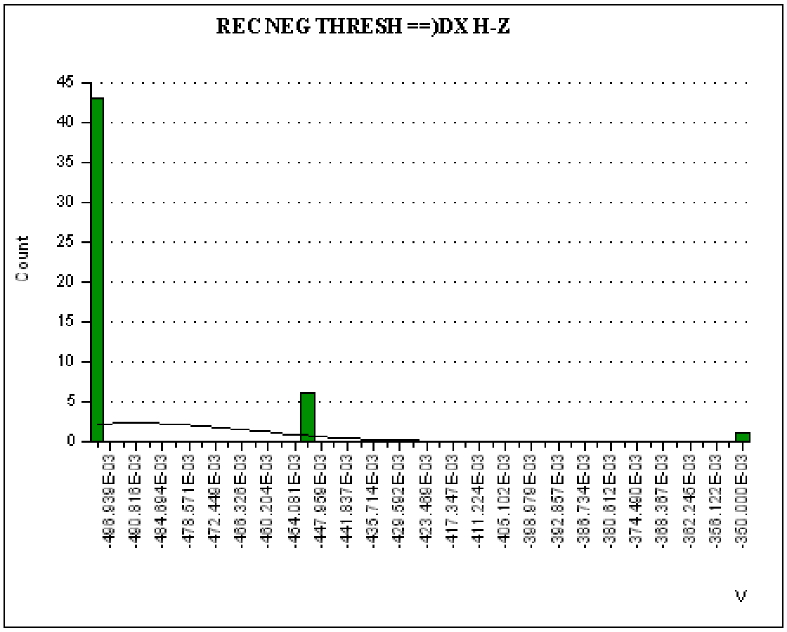
Min	-450.000E-03	**Skew**	2.2725
Max	-400.000E-03	**StatHigh**	N/A
Mean	-443.333E-03	**StatLow**	N/A
StdDev	17.287E-03	**NWithinSpec**	N/A
25%	-450.000E-03	**NOutsideSpec**	N/A
Mean+3*StdDev	-391.471E-03	**90%**	-400.000E-03
		Range	50.000E-03
Mean-3*StdDev	-495.195E-03	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=13.019, Test.Name=REC NEG THRESH ==)DX H-Z



Statistics: (V)

Min	-500.000E-03	**StatLow**	N/A
Max	-350.000E-03	**NWithinSpec**	N/A
Mean	-491.000E-03	**NOutsideSpec**	N/A
StdDev	26.128E-03	**90%**	-450.000E-03
25%	-500.000E-03	**Range**	150.000E-03
Mean+3*StdDev	-412.617E-03	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-569.383E-03	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	3.7966		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

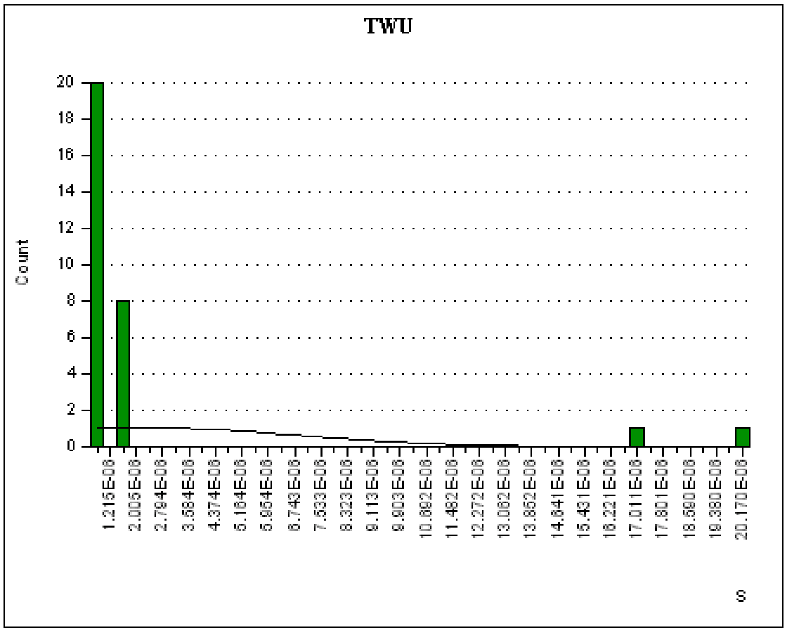
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=14.000, Test.Name=TWU



Statistics: (S)

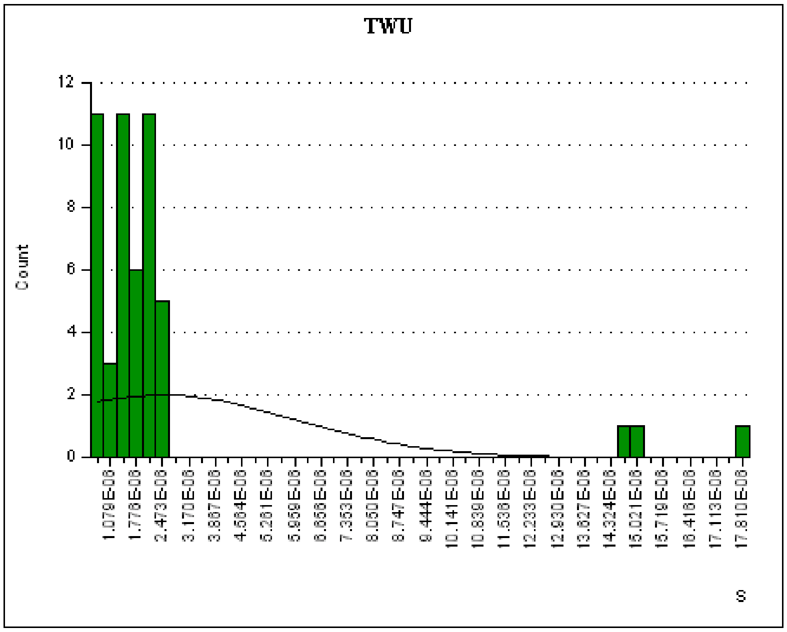
Min	819.999E-09	**Skew**	3.6873
Max	20.170E-06	**StatHigh**	N/A
Mean	2.233E-06	**StatLow**	N/A
StdDev	4.485E-06	**NWithinSpec**	N/A
25%	869.998E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	15.688E-06	**90%**	1.555E-06
		Range	19.350E-06
Mean-3*StdDev	-11.222E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=14.000, Test.Name=TWU



Statistics: (S)

Min	729.999E-09	**StatLow**	N/A
Max	17.810E-06	**NWithinSpec**	N/A
Mean	2.447E-06	**NOutsideSpec**	N/A
StdDev	3.487E-06	**90%**	2.320E-06
25%	1.160E-06	**Range**	17.080E-06
Mean+3*StdDev	12.908E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-8.014E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.7175		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

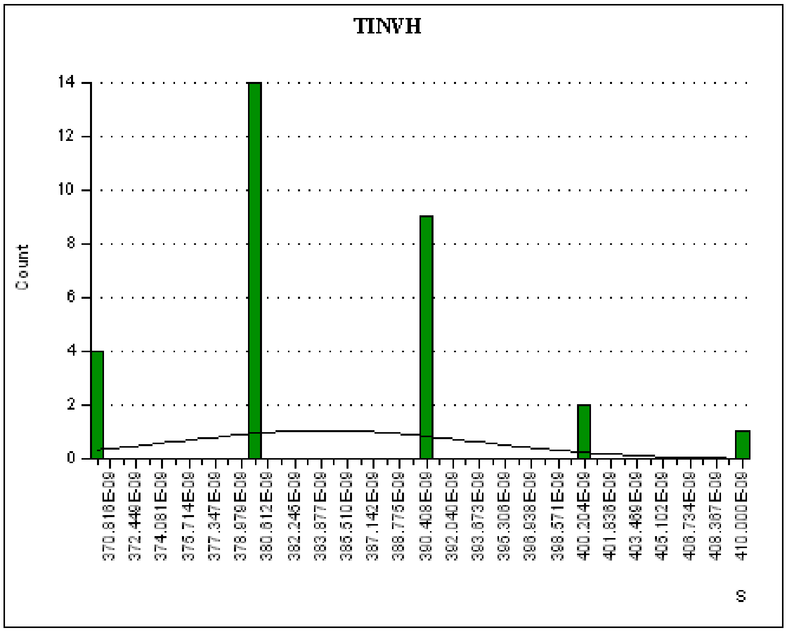
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=15.000, Test.Name=TINVH



Statistics: (S)

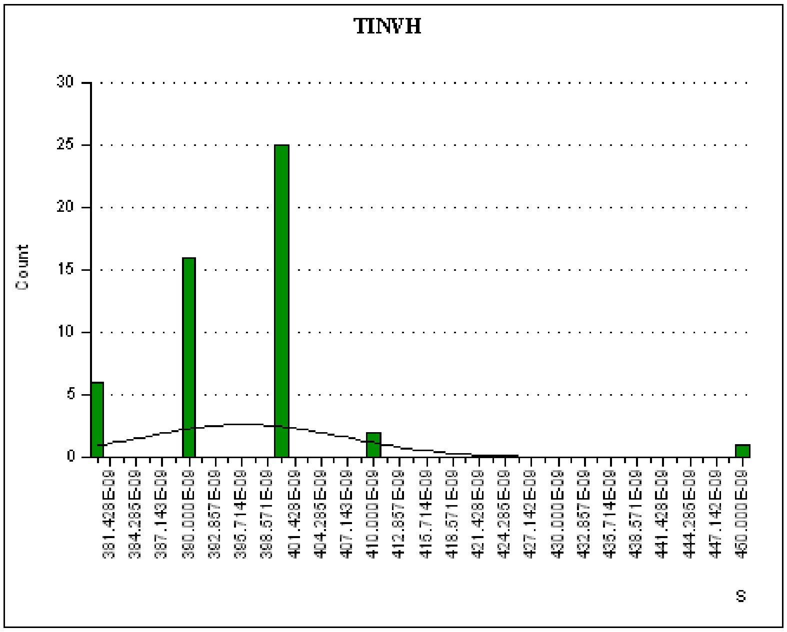
Min	370.000E-09	**Skew**	0.7225
Max	410.000E-09	**StatHigh**	N/A
Mean	384.000E-09	**StatLow**	N/A
StdDev	9.322E-09	**NWithinSpec**	N/A
25%	380.000E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	411.965E-09	**90%**	395.000E-09
		Range	40.000E-09
Mean-3*StdDev	356.034E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=15.000, Test.Name=TINVH



Statistics: (S)

Min	380.000E-09	**StatLow**	N/A
Max	450.000E-09	**NWithinSpec**	N/A
Mean	395.800E-09	**NOutsideSpec**	N/A
StdDev	10.897E-09	**90%**	400.000E-09
25%	390.000E-09	**Range**	70.000E-09
Mean+3*StdDev	428.489E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	363.110E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.3005		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

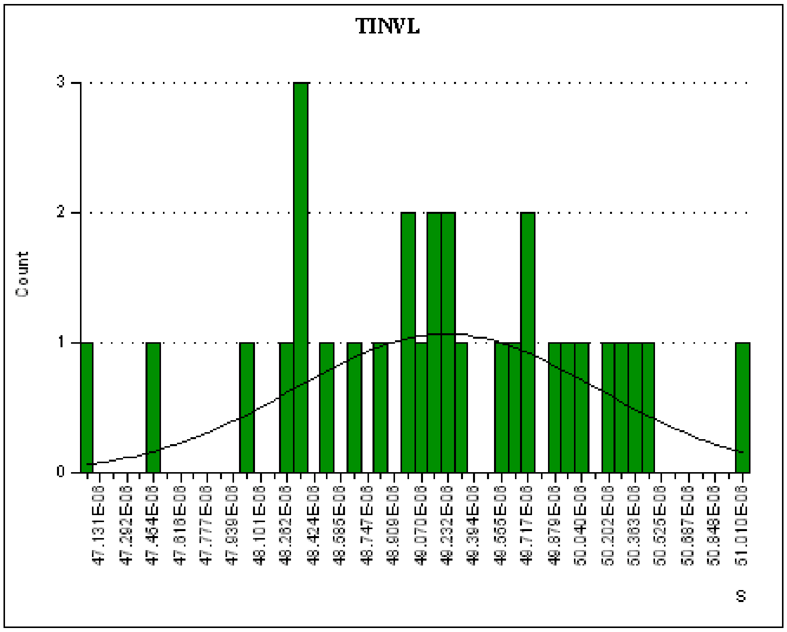
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=15.001, Test.Name=TINVL



Statistics: (S)

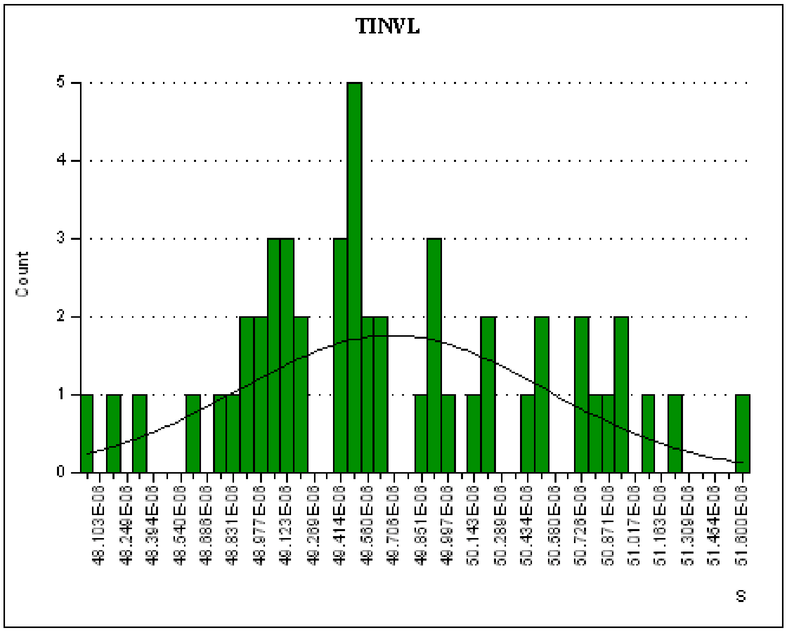
Min	47.050E-06	**Skew**	-0.3106
Max	51.010E-06	**StatHigh**	N/A
Mean	49.198E-06	**StatLow**	N/A
StdDev	905.279E-09	**NWithinSpec**	N/A
25%	48.480E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	51.914E-06	**90%**	50.300E-06
		Range	3.960E-06
Mean-3*StdDev	46.482E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=15.001, Test.Name=TINVL



Statistics: (S)

Min	48.030E-06	**StatLow**	N/A
Max	51.600E-06	**NWithinSpec**	N/A
Mean	49.678E-06	**NOutsideSpec**	N/A
StdDev	824.768E-09	**90%**	50.880E-06
25%	49.070E-06	**Range**	3.570E-06
Mean+3*StdDev	52.152E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	47.203E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.3200		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

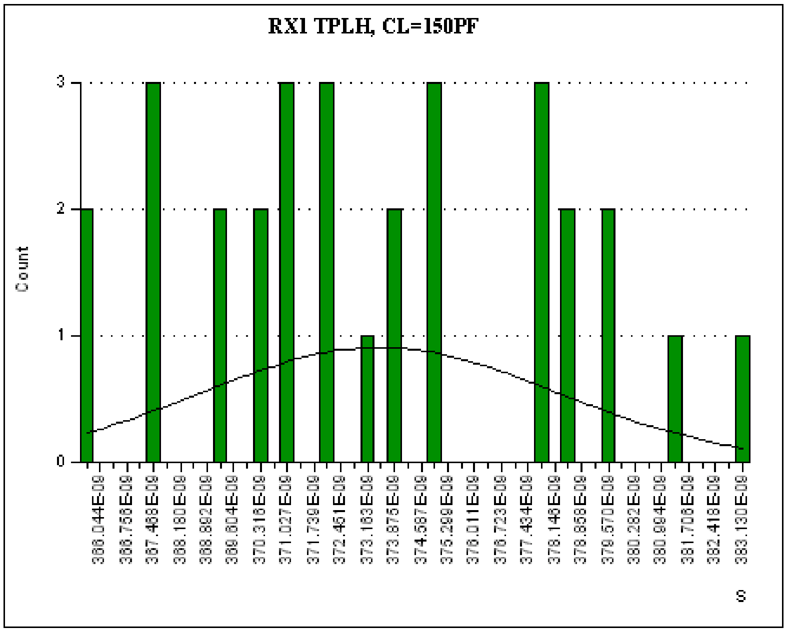
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.000, Test.Name=RX1 TPLH, CL=150PF



Statistics: (S)

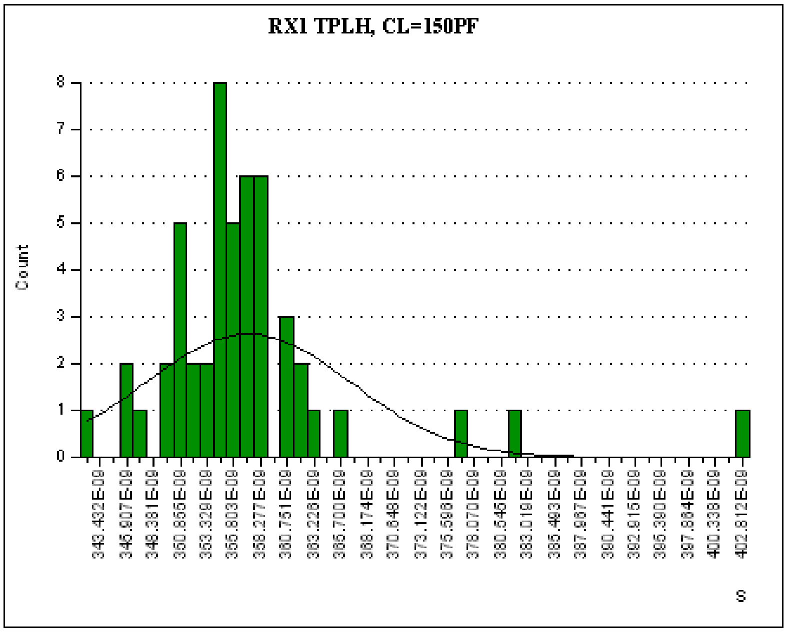
Min	365.688E-09	**Skew**	0.2181
Max	383.130E-09	**StatHigh**	N/A
Mean	373.399E-09	**StatLow**	N/A
StdDev	4.691E-09	**NWithinSpec**	N/A
25%	370.278E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	387.471E-09	**90%**	379.458E-09
		Range	17.441E-09
Mean-3*StdDev	359.327E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.000, Test.Name=RX1 TPLH, CL=150PF



Statistics: (S)

Min	342.195E-09	**StatLow**	N/A
Max	402.812E-09	**NWithinSpec**	N/A
Mean	356.982E-09	**NOutsideSpec**	N/A
StdDev	9.389E-09	**90%**	362.860E-09
25%	352.298E-09	**Range**	60.617E-09
Mean+3*StdDev	385.148E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	328.816E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.8661		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

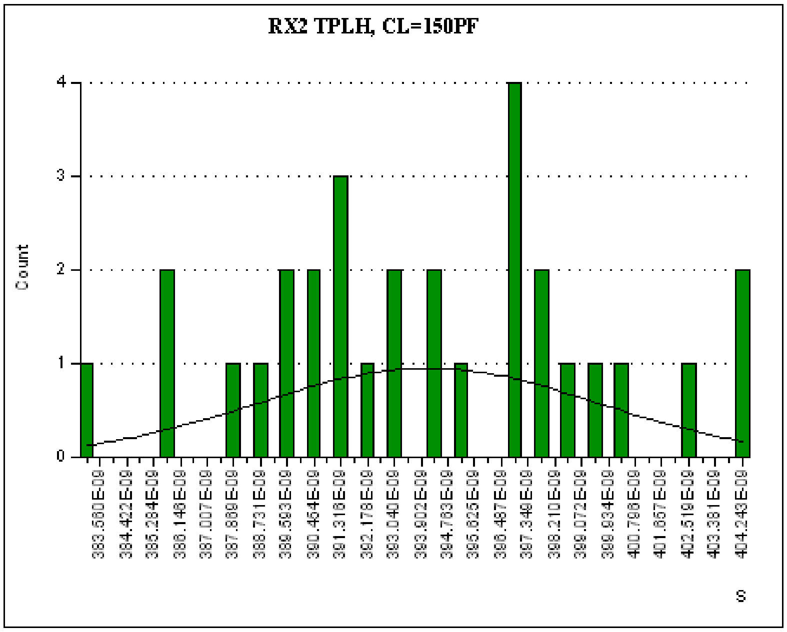
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.001, Test.Name=RX2 TPLH, CL=150PF



Statistics: (S)

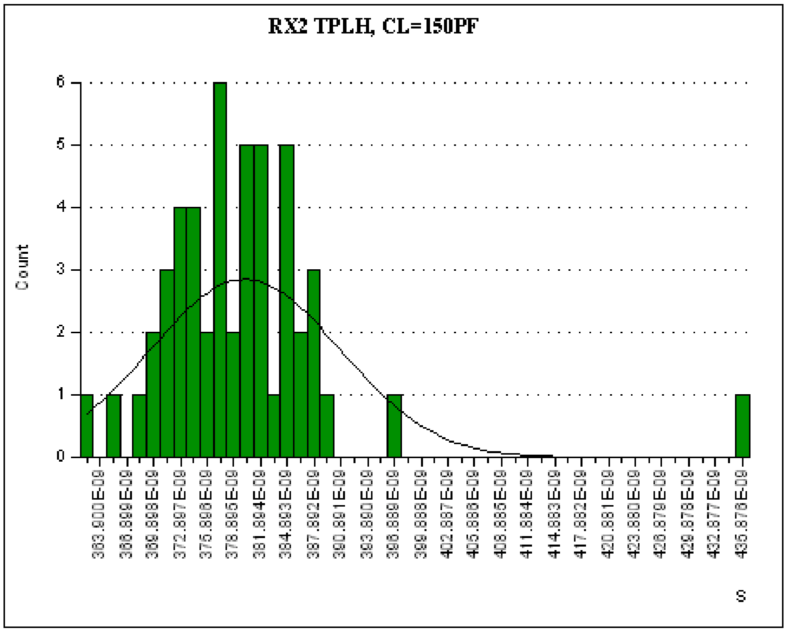
Min	383.130E-09	**Skew**	0.0904
Max	404.243E-09	**StatHigh**	N/A
Mean	394.023E-09	**StatLow**	N/A
StdDev	5.411E-09	**NWithinSpec**	N/A
25%	390.473E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	410.254E-09	**90%**	401.489E-09
		Range	21.113E-09
Mean-3*StdDev	377.791E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.001, Test.Name=RX2 TPLH, CL=150PF



Statistics: (S)

Min	362.401E-09	**StatLow**	N/A
Max	435.876E-09	**NWithinSpec**	N/A
Mean	379.925E-09	**NOutsideSpec**	N/A
StdDev	10.488E-09	**90%**	387.199E-09
25%	374.341E-09	**Range**	73.475E-09
Mean+3*StdDev	411.388E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	348.461E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.1014		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

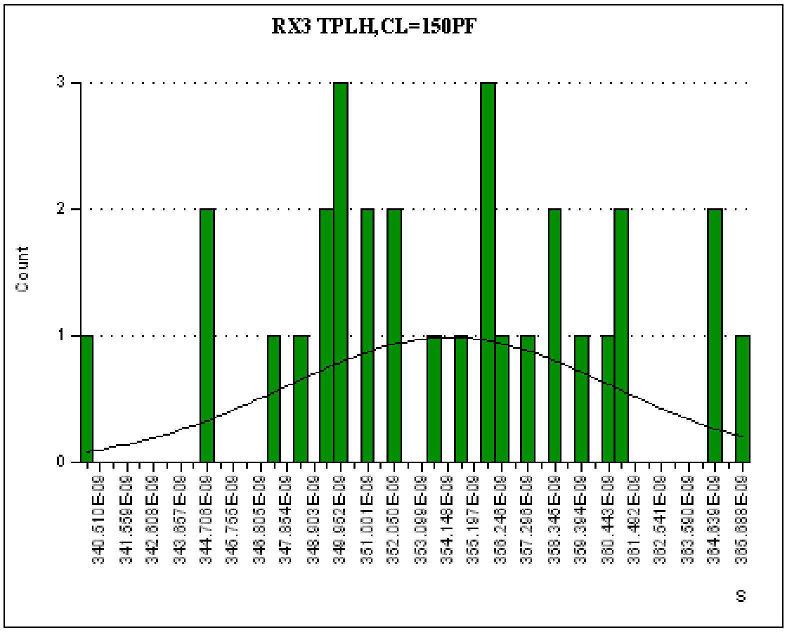
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.002, Test.Name=RX3 TPLH,CL=150PF



Statistics: (S)

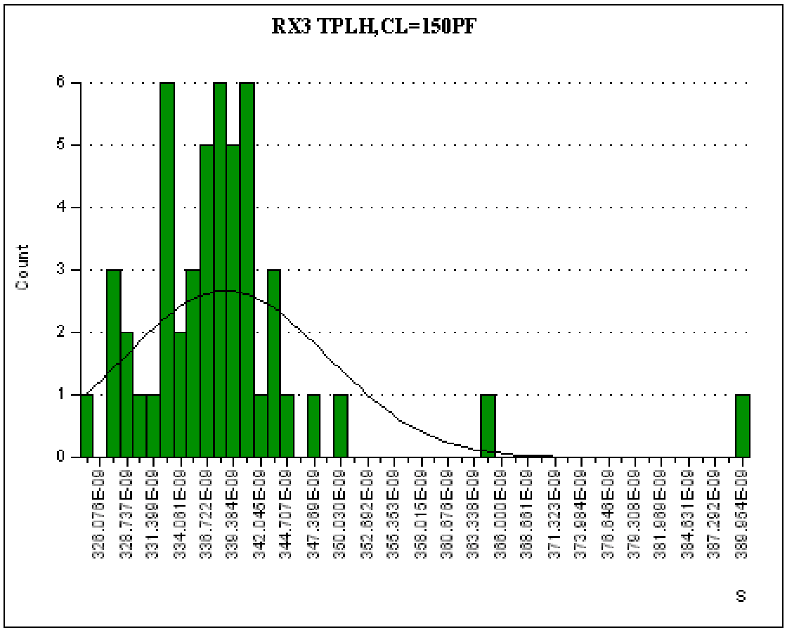
Min	339.985E-09	**Skew**	-0.0261
Max	365.688E-09	**StatHigh**	N/A
Mean	354.061E-09	**StatLow**	N/A
StdDev	6.352E-09	**NWithinSpec**	N/A
25%	350.083E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	373.117E-09	**90%**	362.934E-09
		Range	25.703E-09
Mean-3*StdDev	335.004E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.002, Test.Name=RX3 TPLH,CL=150PF



Statistics: (S)

Min	324.745E-09	**StatLow**	N/A
Max	389.954E-09	**NWithinSpec**	N/A
Mean	338.430E-09	**NOutsideSpec**	N/A
StdDev	9.937E-09	**90%**	344.491E-09
25%	333.011E-09	**Range**	65.209E-09
Mean+3*StdDev	368.242E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	308.617E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	3.1837		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

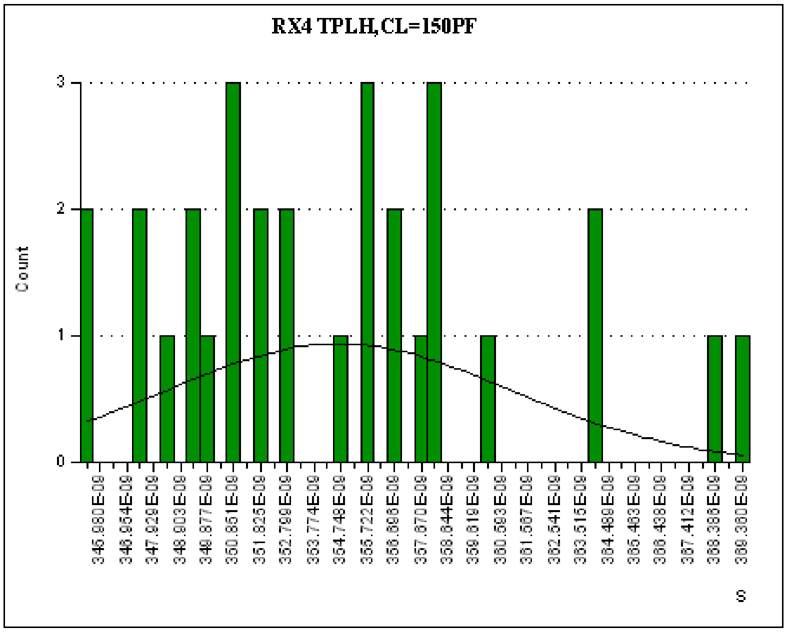
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.003, Test.Name=RX4 TPLH,CL=150PF



Statistics: (S)

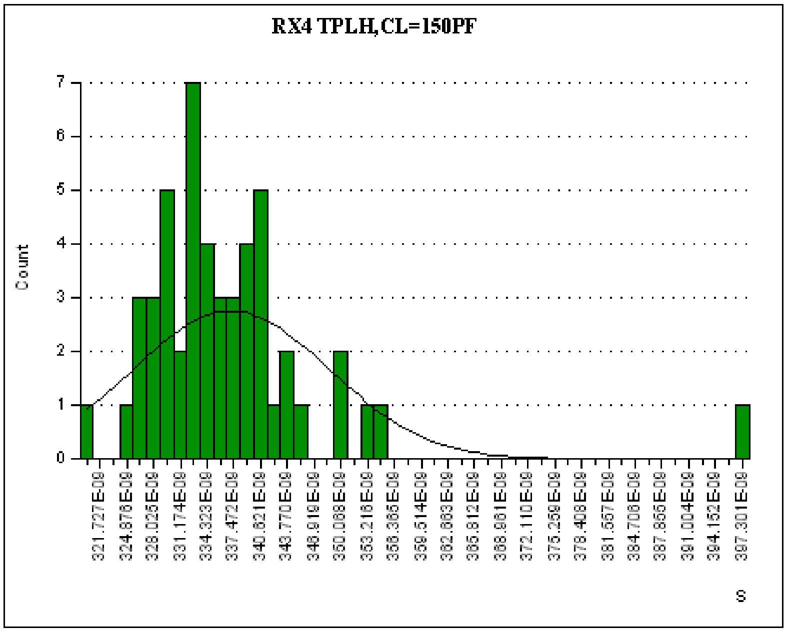
Min	345.493E-09	**Skew**	0.7280
Max	369.360E-09	**StatHigh**	N/A
Mean	354.581E-09	**StatLow**	N/A
StdDev	6.223E-09	**NWithinSpec**	N/A
25%	350.083E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	373.250E-09	**90%**	363.852E-09
		Range	23.867E-09
Mean-3*StdDev	335.912E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.003, Test.Name=RX4 TPLH,CL=150PF



Statistics: (S)

Min	320.153E-09	**StatLow**	N/A
Max	397.301E-09	**NWithinSpec**	N/A
Mean	336.942E-09	**NOutsideSpec**	N/A
StdDev	11.388E-09	**90%**	347.247E-09
25%	330.256E-09	**Range**	77.149E-09
Mean+3*StdDev	371.107E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	302.776E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.1810		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

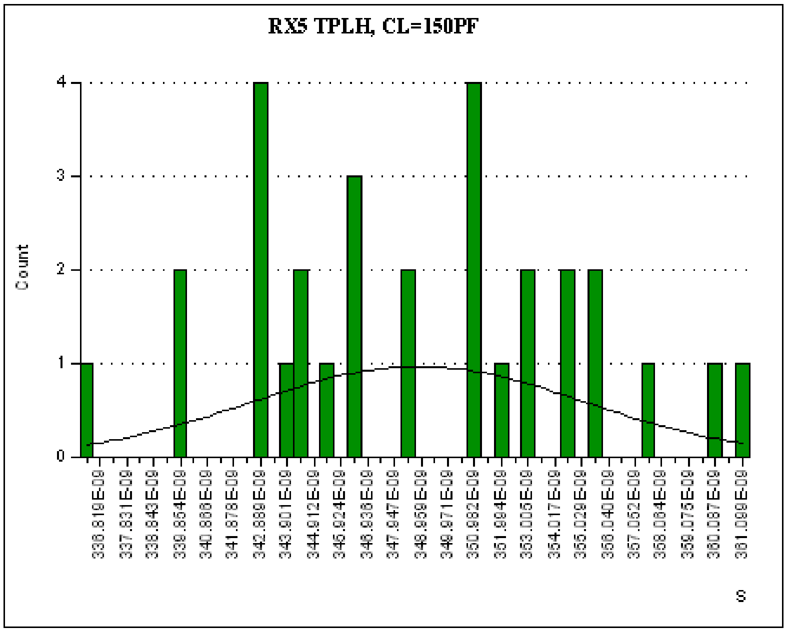
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.004, Test.Name=RX5 TPLH, CL=150PF



Statistics: (S)

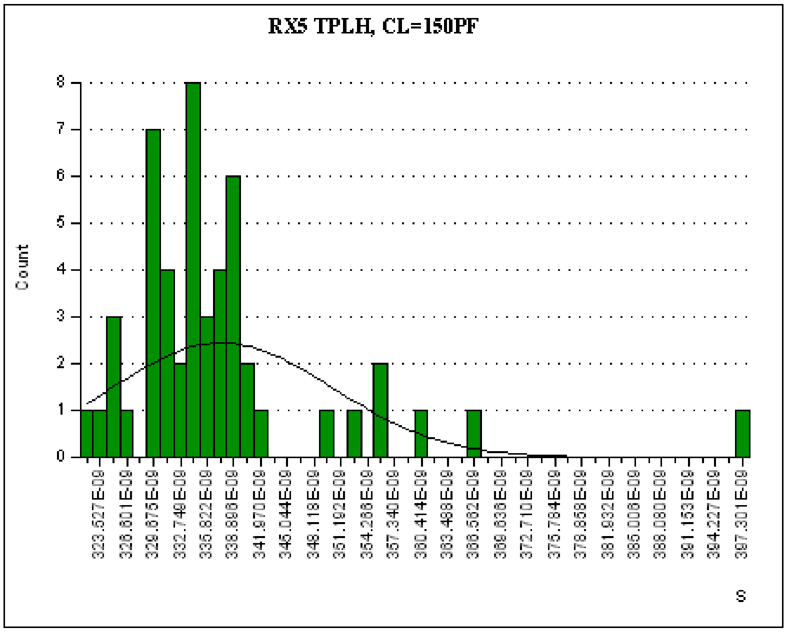
Min	336.314E-09	**Skew**	0.1304
Max	361.099E-09	**StatHigh**	N/A
Mean	348.737E-09	**StatLow**	N/A
StdDev	6.234E-09	**NWithinSpec**	N/A
25%	343.657E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	367.439E-09	**90%**	356.509E-09
		Range	24.785E-09
Mean-3*StdDev	330.035E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.004, Test.Name=RX5 TPLH, CL=150PF



Statistics: (S)

Min	321.990E-09	**StatLow**	N/A
Max	397.301E-09	**NWithinSpec**	N/A
Mean	337.383E-09	**NOutsideSpec**	N/A
StdDev	12.557E-09	**90%**	353.676E-09
25%	330.256E-09	**Range**	75.312E-09
Mean+3*StdDev	375.053E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	299.712E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	2.7082		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

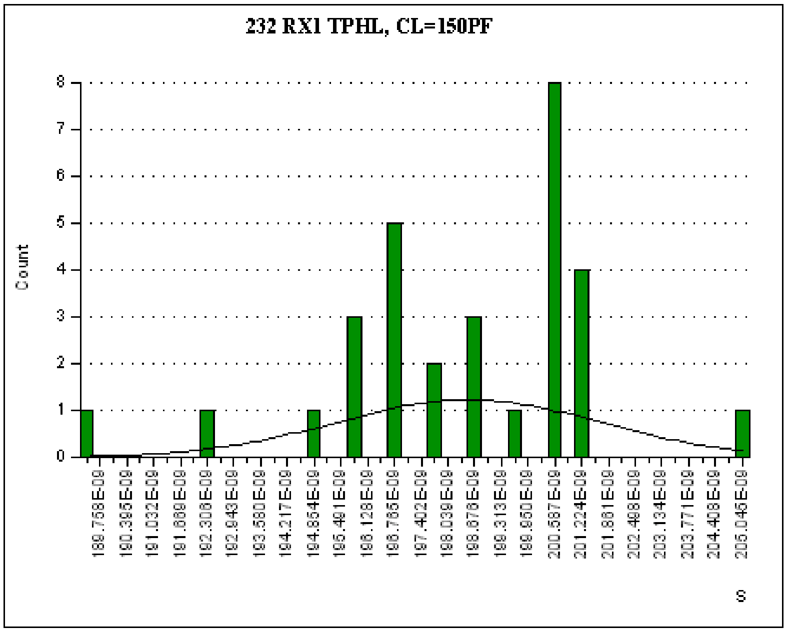
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.005, Test.Name=232 RX1 TPHL, CL=150PF



Statistics: (S)

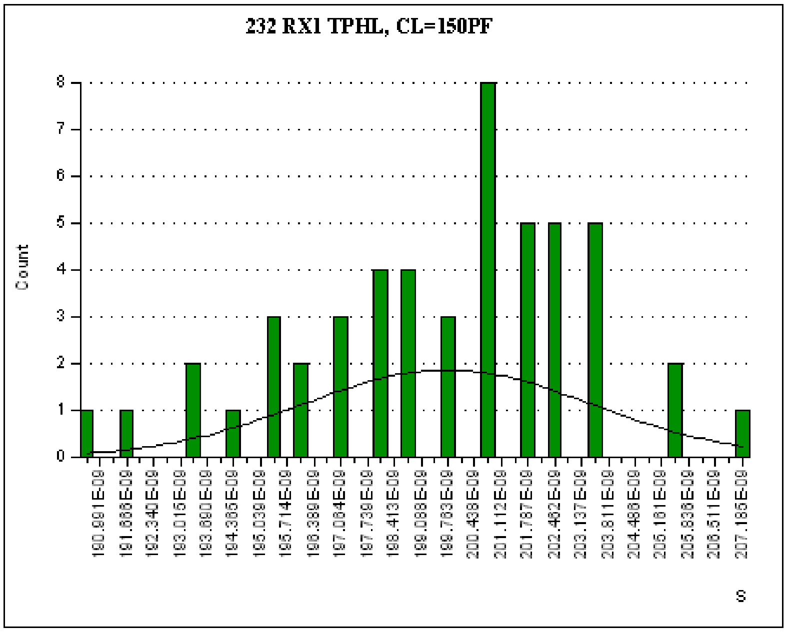
Min	189.440E-09	**Skew**	-0.7818
Max	205.045E-09	**StatHigh**	N/A
Mean	198.436E-09	**StatLow**	N/A
StdDev	3.100E-09	**NWithinSpec**	N/A
25%	196.784E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	207.737E-09	**90%**	201.373E-09
		Range	15.605E-09
Mean-3*StdDev	189.135E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.005, Test.Name=232 RX1 TPHL, CL=150PF



Statistics: (S)

Min	190.653E-09	**StatLow**	N/A
Max	207.185E-09	**NWithinSpec**	N/A
Mean	199.654E-09	**NOutsideSpec**	N/A
StdDev	3.608E-09	**90%**	203.512E-09
25%	197.082E-09	**Range**	16.532E-09
Mean+3*StdDev	210.477E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	188.831E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.4736		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

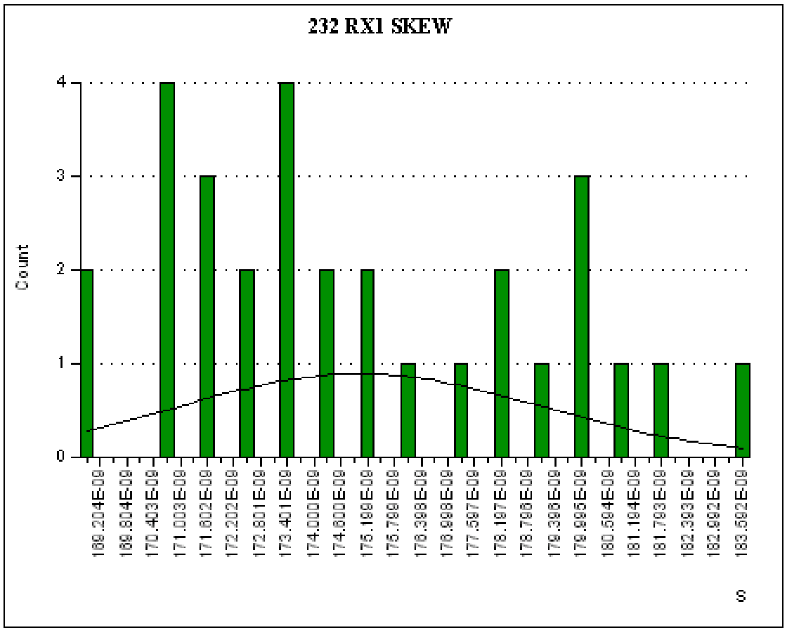
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.006, Test.Name=232 RX1 SKEW



Statistics: (S)

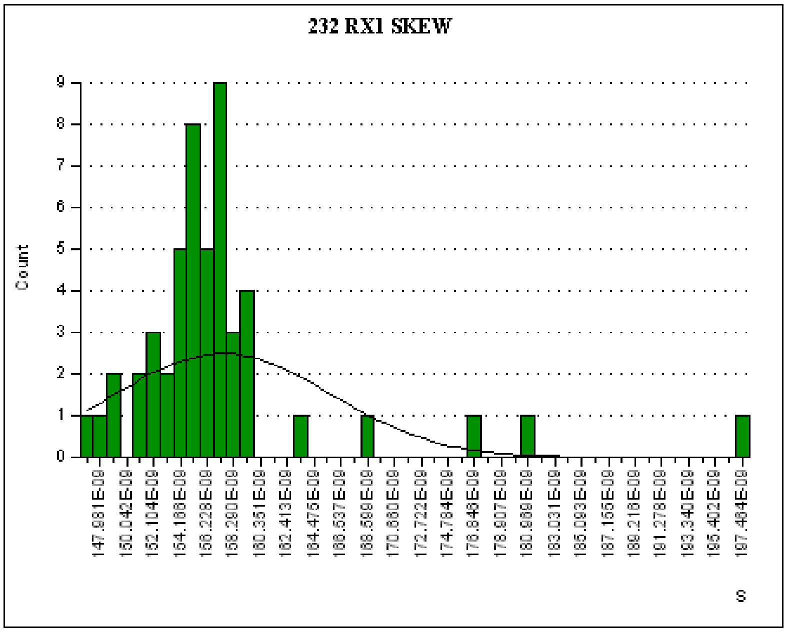
Min	168.905E-09	**Skew**	0.4363
Max	183.592E-09	**StatHigh**	N/A
Mean	174.963E-09	**StatLow**	N/A
StdDev	4.024E-09	**NWithinSpec**	N/A
25%	171.658E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	187.034E-09	**90%**	180.379E-09
		Range	14.687E-09
Mean-3*StdDev	162.892E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.006, Test.Name=232 RX1 SKEW



Statistics: (S)

Min	146.950E-09	**StatLow**	N/A
Max	197.464E-09	**NWithinSpec**	N/A
Mean	157.328E-09	**NOutsideSpec**	N/A
StdDev	8.259E-09	**90%**	161.645E-09
25%	154.297E-09	**Range**	50.514E-09
Mean+3*StdDev	182.105E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	132.551E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.1001		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

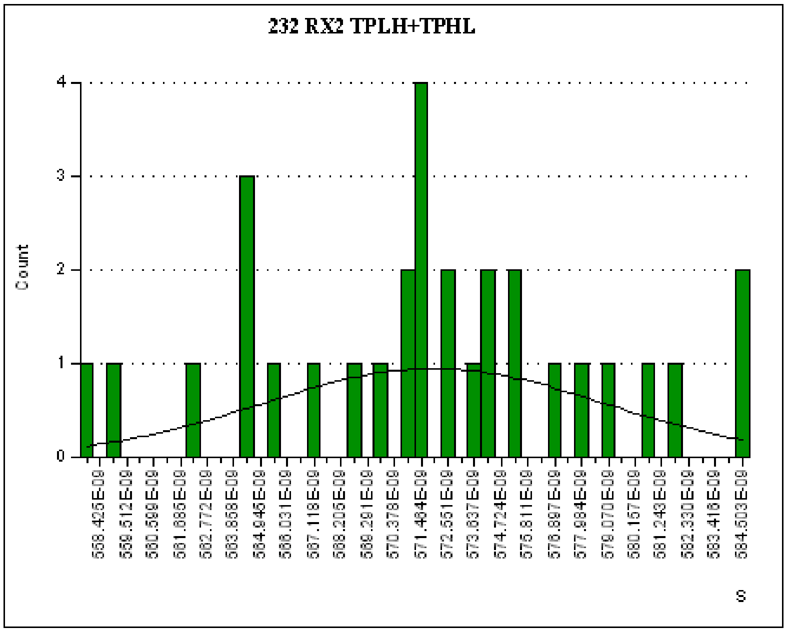
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.007, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

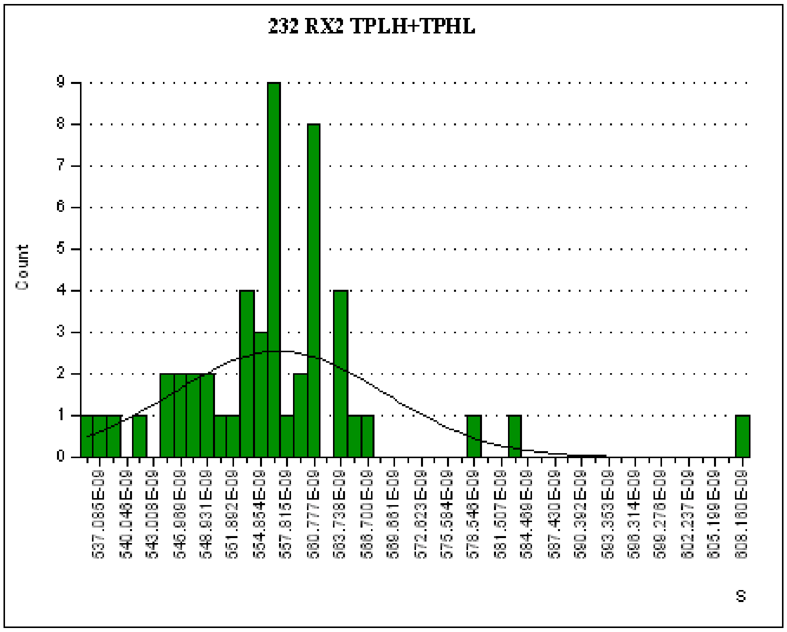
Min	557.882E-09	**Skew**	-0.0930
Max	584.503E-09	**StatHigh**	N/A
Mean	571.835E-09	**StatLow**	N/A
StdDev	6.858E-09	**NWithinSpec**	N/A
25%	567.062E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	592.410E-09	**90%**	581.290E-09
		Range	26.621E-09
Mean-3*StdDev	551.260E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.007, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

Min	535.604E-09	**StatLow**	N/A
Max	608.160E-09	**NWithinSpec**	N/A
Mean	556.636E-09	**NOutsideSpec**	N/A
StdDev	11.581E-09	**90%**	564.535E-09
25%	550.299E-09	**Range**	72.556E-09
Mean+3*StdDev	591.378E-09	**NOutsideSpec**	N/A
Mean-3*StdDev	521.894E-09	**Cp**	N/A
Cpk	N/A	**Cpl**	N/A
Skew	1.8081	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

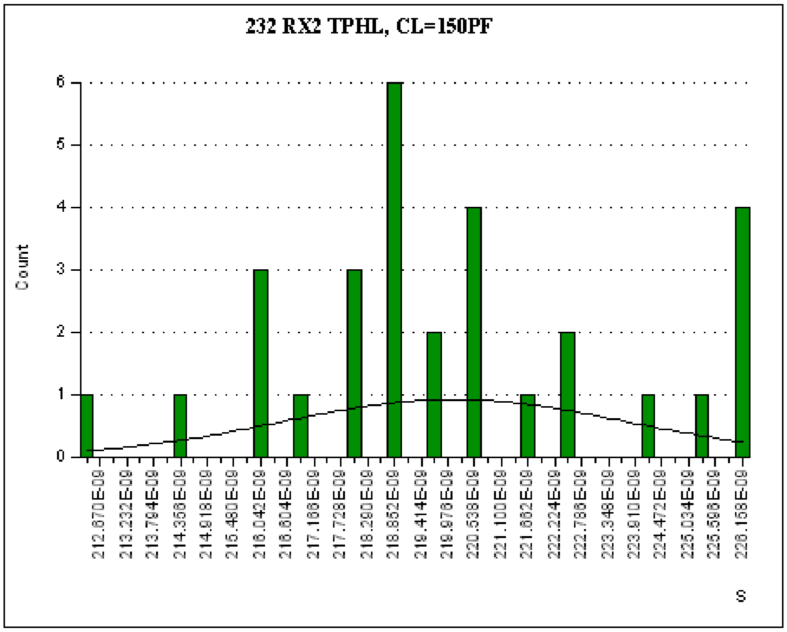
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.008, Test.Name=232 RX2 TPHL, CL=150PF



Statistics: (S)

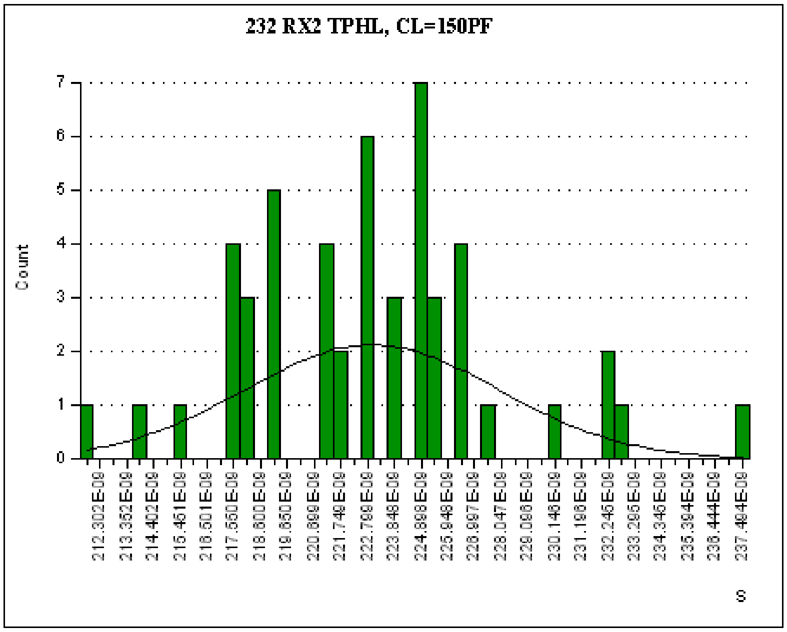
Min	212.389E-09	**Skew**	0.2061
Max	226.158E-09	**StatHigh**	N/A
Mean	220.039E-09	**StatLow**	N/A
StdDev	3.635E-09	**NWithinSpec**	N/A
25%	217.897E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	230.943E-09	**90%**	226.158E-09
		Range	13.769E-09
Mean-3*StdDev	209.135E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.008, Test.Name=232 RX2 TPHL, CL=150PF



Statistics: (S)

Min	211.777E-09	**StatLow**	N/A
Max	237.494E-09	**NWithinSpec**	N/A
Mean	222.854E-09	**NOutsideSpec**	N/A
StdDev	4.932E-09	**90%**	228.768E-09
25%	219.125E-09	**Range**	25.716E-09
Mean+3*StdDev	237.649E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	208.059E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.4631		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

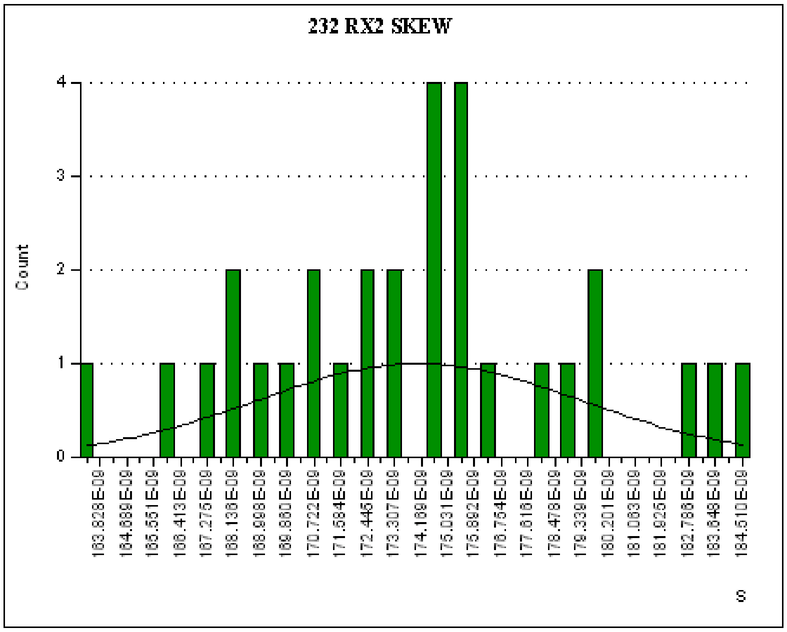
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.009, Test.Name=232 RX2 SKEW



Statistics: (S)

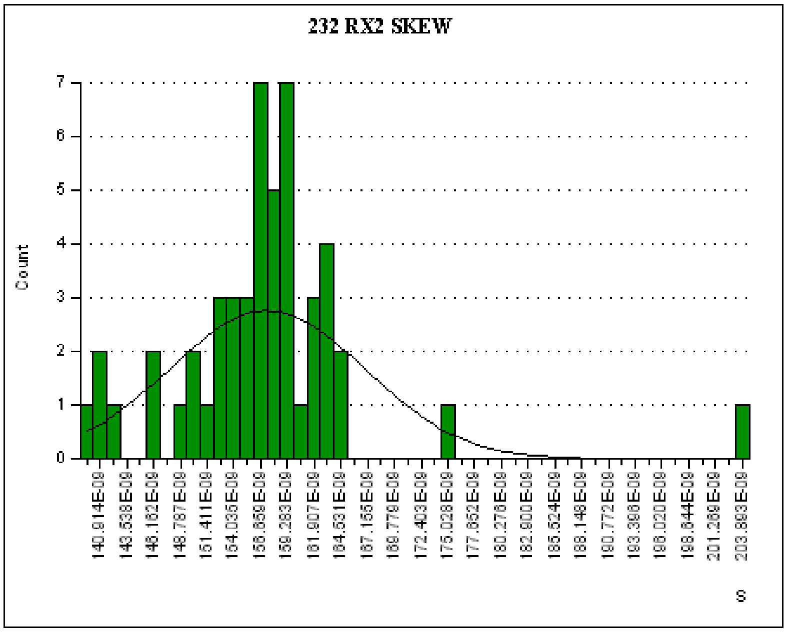
Min	163.397E-09	**Skew**	0.1685
Max	184.510E-09	**StatHigh**	N/A
Mean	173.984E-09	**StatLow**	N/A
StdDev	5.158E-09	**NWithinSpec**	N/A
25%	170.740E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	189.457E-09	**90%**	181.297E-09
		Range	21.113E-09
Mean-3*StdDev	158.511E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.009, Test.Name=232 RX2 SKEW



Statistics: (S)

Min	139.602E-09	**StatLow**	N/A
Max	203.893E-09	**NWithinSpec**	N/A
Mean	157.071E-09	**NOutsideSpec**	N/A
StdDev	9.480E-09	**90%**	163.482E-09
25%	153.379E-09	**Range**	64.290E-09
Mean+3*StdDev	185.512E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	128.630E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.2331		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

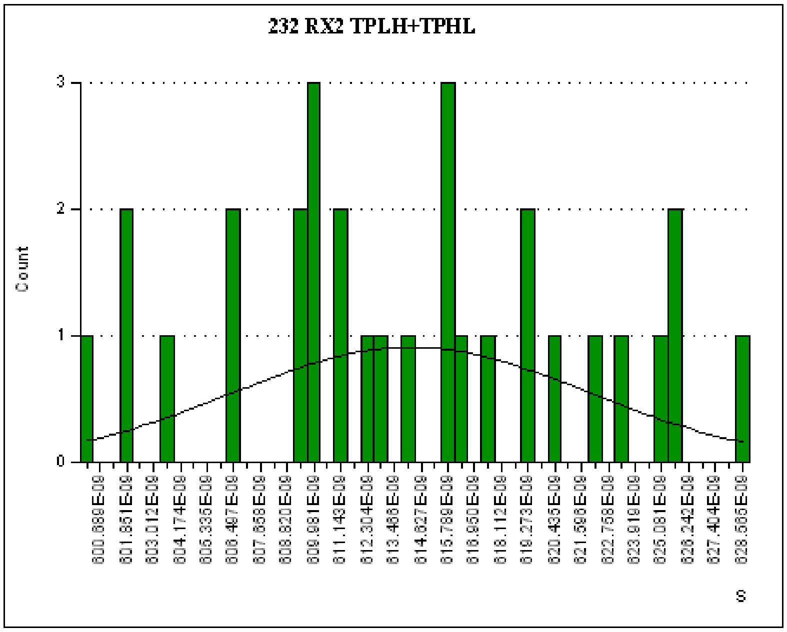
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.010, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

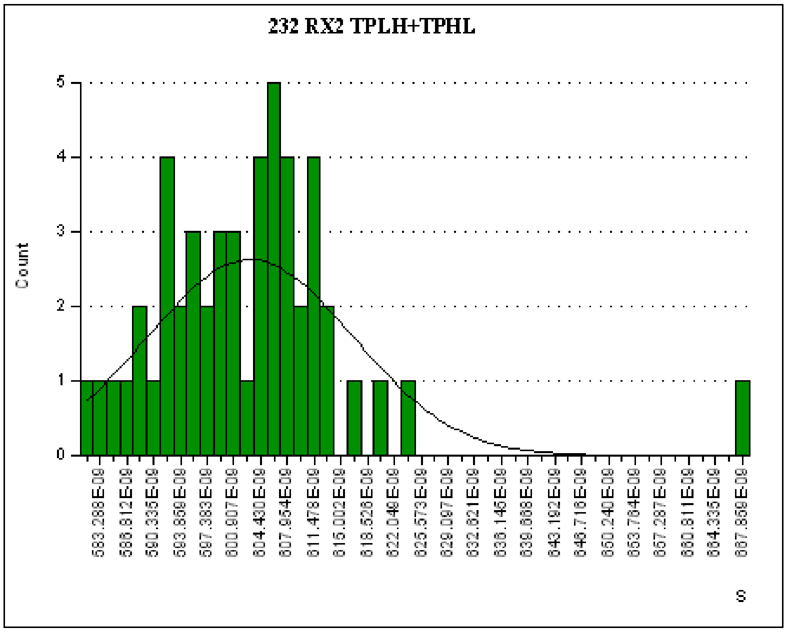
Min	600.108E-09	**Skew**	0.0642
Max	628.565E-09	**StatHigh**	N/A
Mean	614.061E-09	**StatLow**	N/A
StdDev	7.640E-09	**NWithinSpec**	N/A
25%	609.288E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	636.981E-09	**90%**	625.352E-09
		Range	28.457E-09
Mean-3*StdDev	591.141E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.010, Test.Name=232 RX2 TPLH+TPHL



Statistics: (S)

Min	581.526E-09	**StatLow**	N/A
Max	667.859E-09	**NWithinSpec**	N/A
Mean	602.778E-09	**NOutsideSpec**	N/A
StdDev	13.370E-09	**90%**	612.753E-09
25%	594.384E-09	**Range**	86.333E-09
Mean+3*StdDev	642.889E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	562.668E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.2774		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

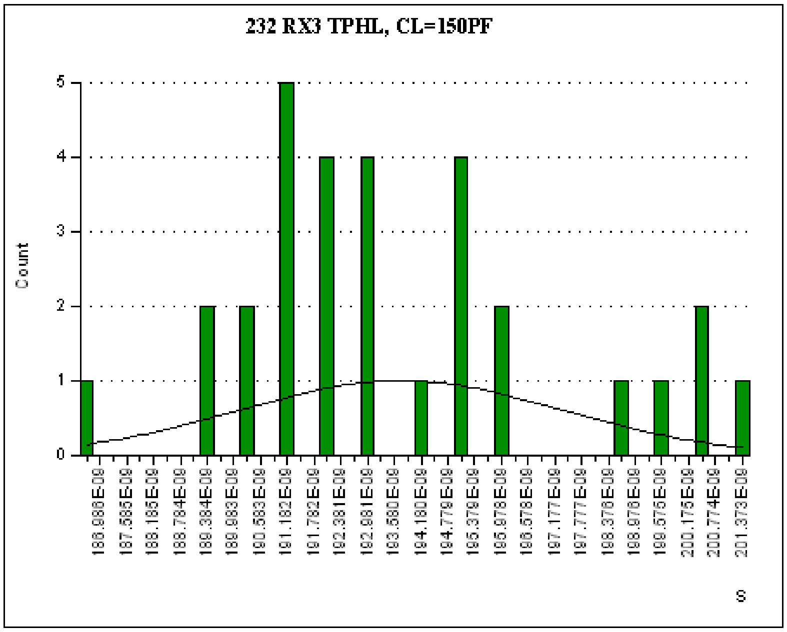
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.011, Test.Name=232 RX3 TPHL, CL=150PF



Statistics: (S)

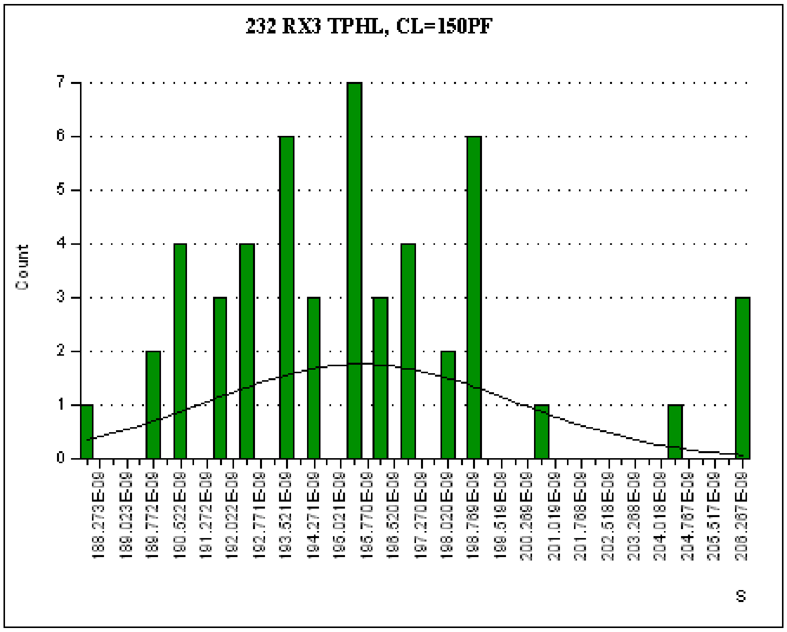
Min	186.686E-09	**Skew**	0.6409
Max	201.373E-09	**StatHigh**	N/A
Mean	193.663E-09	**StatLow**	N/A
StdDev	3.580E-09	**NWithinSpec**	N/A
25%	191.276E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	204.404E-09	**90%**	199.997E-09
		Range	14.687E-09
Mean-3*StdDev	182.921E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.011, Test.Name=232 RX3 TPHL, CL=150PF



Statistics: (S)

Min	187.898E-09	**StatLow**	N/A
Max	206.267E-09	**NWithinSpec**	N/A
Mean	195.503E-09	**NOutsideSpec**	N/A
StdDev	4.240E-09	**90%**	199.838E-09
25%	192.490E-09	**Range**	18.369E-09
Mean+3*StdDev	208.221E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	182.784E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.9077		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

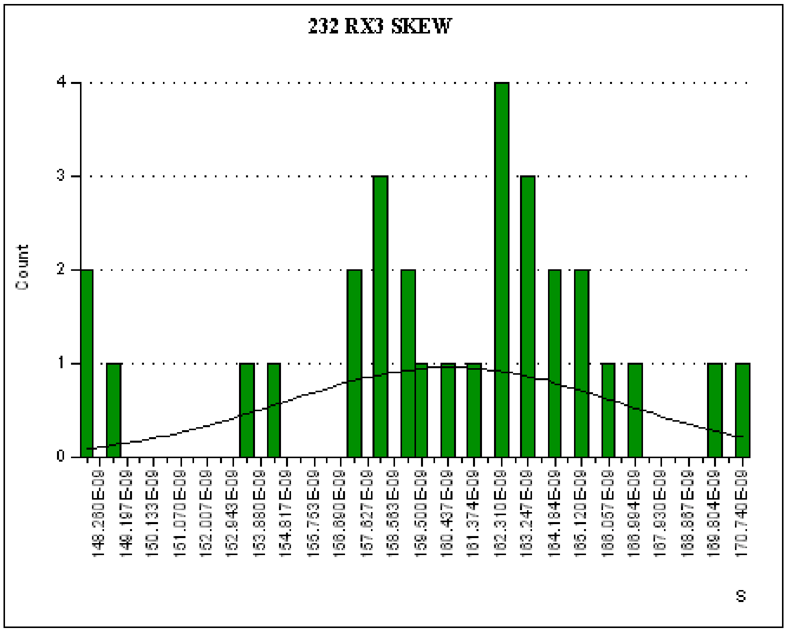
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.012, Test.Name=232 RX3 SKEW



Statistics: (S)

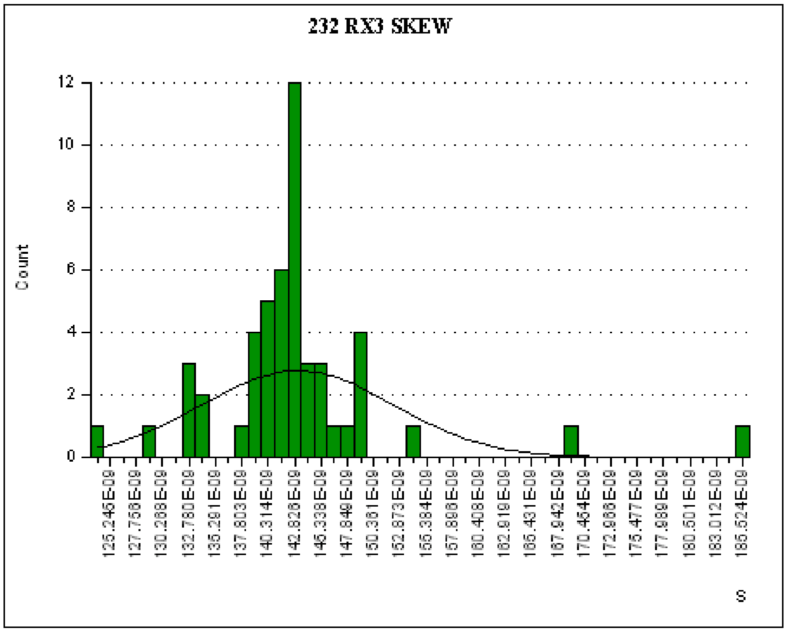
Min	147.792E-09	**Skew**	-0.6395
Max	170.740E-09	**StatHigh**	N/A
Mean	160.398E-09	**StatLow**	N/A
StdDev	5.835E-09	**NWithinSpec**	N/A
25%	157.889E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	177.904E-09	**90%**	166.610E-09
		Range	22.949E-09
Mean-3*StdDev	142.892E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.012, Test.Name=232 RX3 SKEW



Statistics: (S)

Min	123.989E-09	**StatLow**	N/A
Max	185.524E-09	**NWithinSpec**	N/A
Mean	142.927E-09	**NOutsideSpec**	N/A
StdDev	9.018E-09	**90%**	149.246E-09
25%	140.521E-09	**Range**	61.535E-09
Mean+3*StdDev	169.980E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	115.874E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.4142		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

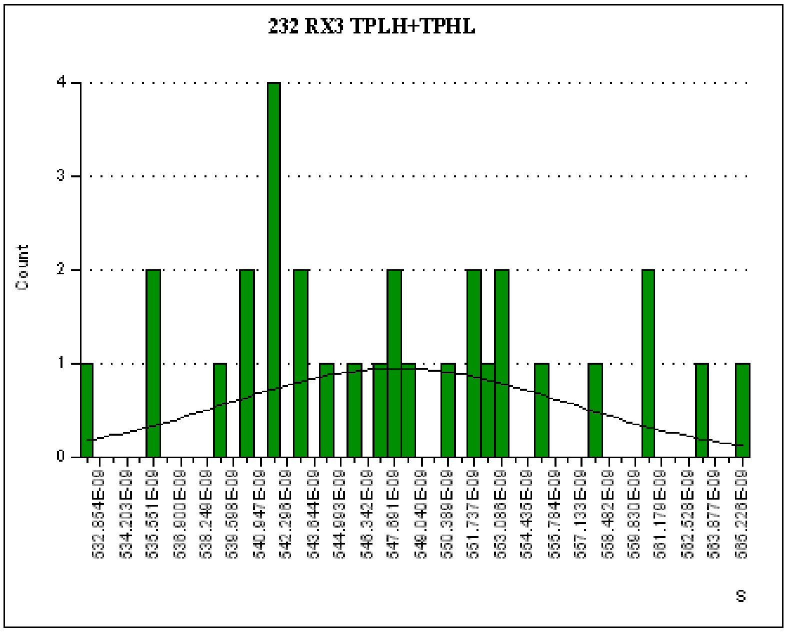
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.013, Test.Name=232 RX3 TPLH+TPHL



Statistics: (S)

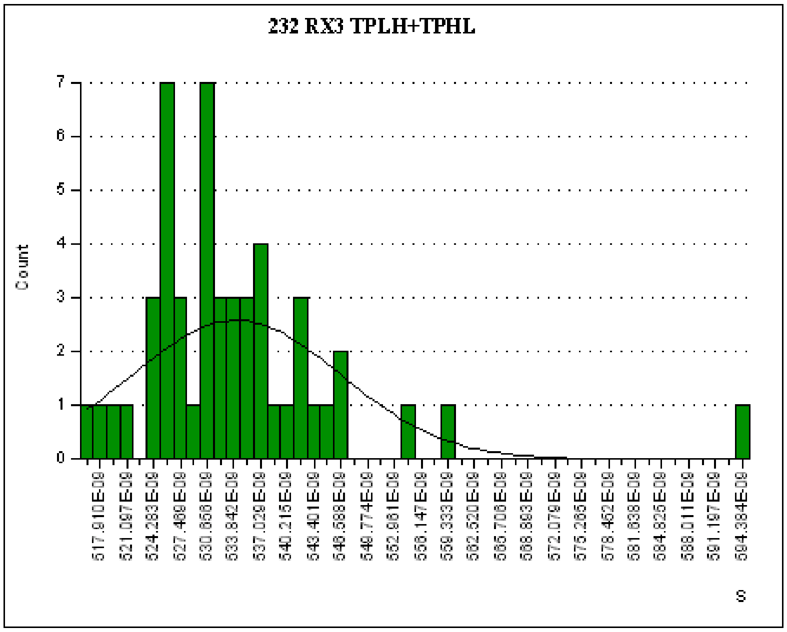
Min	532.179E-09	**Skew**	0.3388
Max	565.226E-09	**StatHigh**	N/A
Mean	547.723E-09	**StatLow**	N/A
StdDev	8.502E-09	**NWithinSpec**	N/A
25%	541.359E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	573.230E-09	**90%**	560.636E-09
		Range	33.046E-09
Mean-3*StdDev	522.216E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.013, Test.Name=232 RX3 TPLH+TPHL



Statistics: (S)

Min	516.317E-09	**StatLow**	N/A
Max	594.384E-09	**NWithinSpec**	N/A
Mean	533.932E-09	**NOutsideSpec**	N/A
StdDev	12.334E-09	**90%**	546.166E-09
25%	525.501E-09	**Range**	78.067E-09
Mean+3*StdDev	570.935E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	496.930E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.6162		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

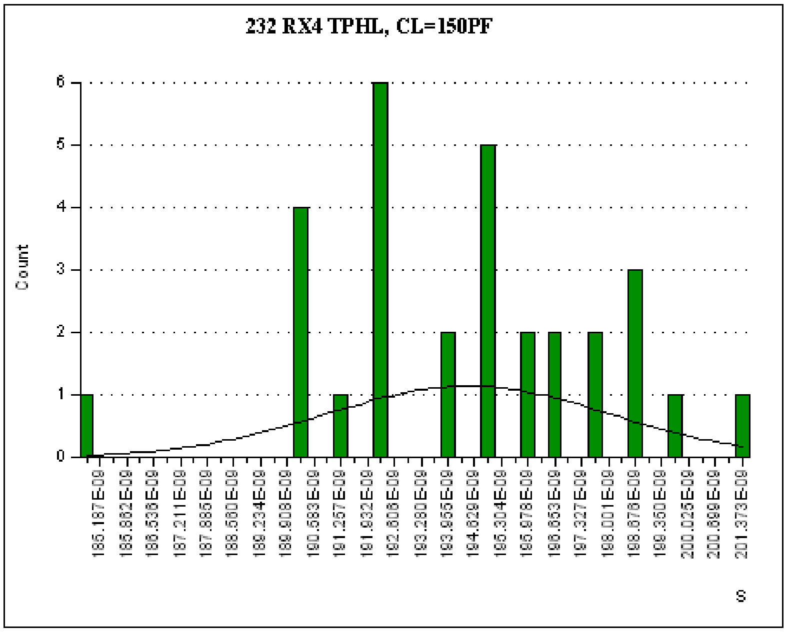
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.014, Test.Name=232 RX4 TPHL, CL=150PF



Statistics: (S)

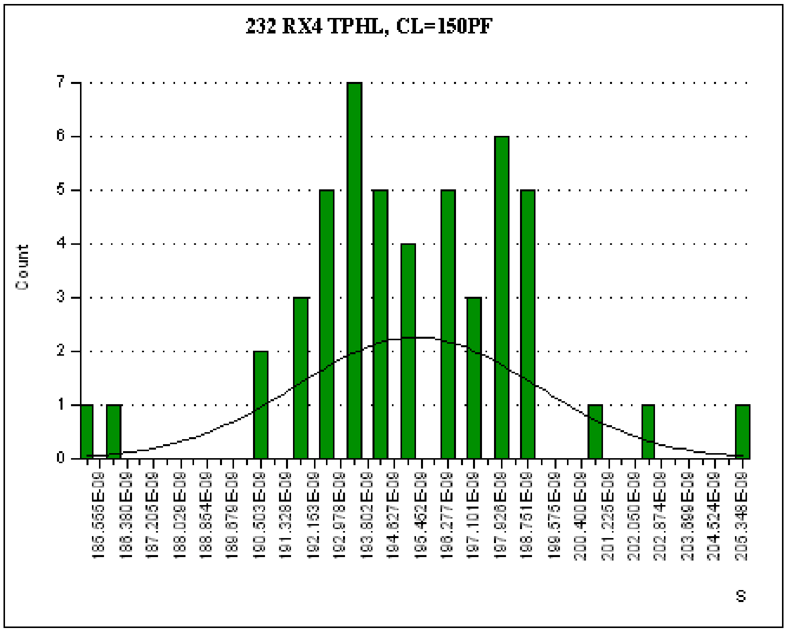
Min	184.850E-09	**Skew**	-0.3228
Max	201.373E-09	**StatHigh**	N/A
Mean	194.366E-09	**StatLow**	N/A
StdDev	3.539E-09	**NWithinSpec**	N/A
25%	192.194E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	204.983E-09	**90%**	198.620E-09
		Range	16.523E-09
Mean-3*StdDev	183.750E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.014, Test.Name=232 RX4 TPHL, CL=150PF



Statistics: (S)

Min	185.143E-09	**StatLow**	N/A
Max	205.348E-09	**NWithinSpec**	N/A
Mean	195.191E-09	**NOutsideSpec**	N/A
StdDev	3.638E-09	**90%**	198.919E-09
25%	193.409E-09	**Range**	20.206E-09
Mean+3*StdDev	206.105E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	184.277E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.0891		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

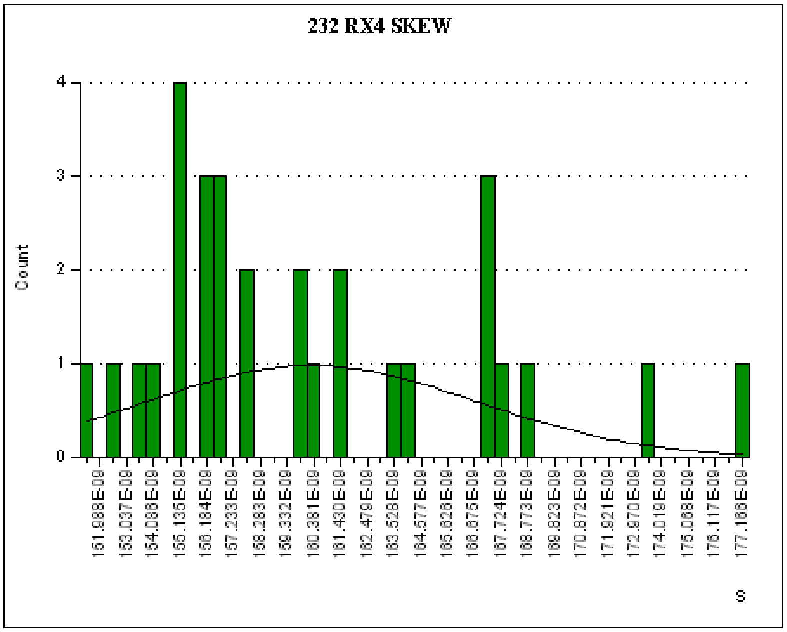
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.015, Test.Name=232 RX4 SKEW



Statistics: (S)

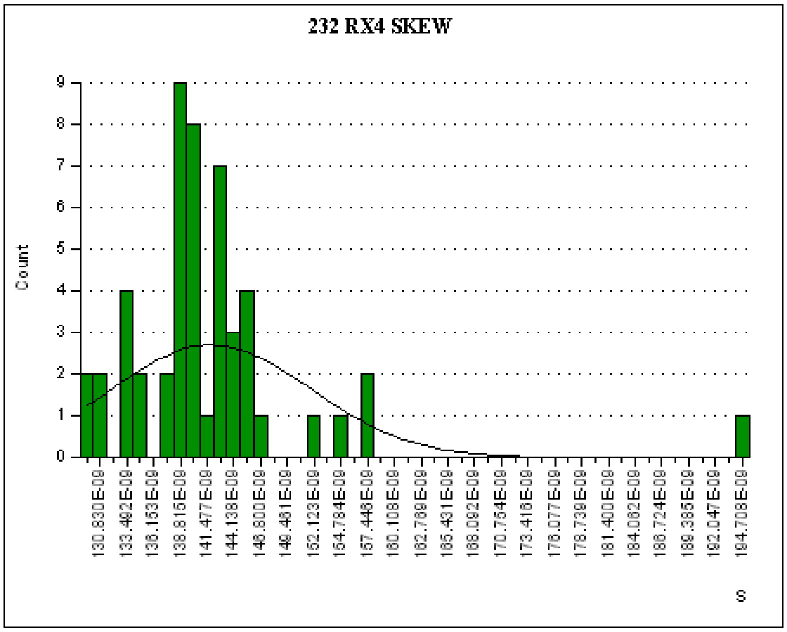
Min	151.463E-09	**Skew**	0.9609
Max	177.166E-09	**StatHigh**	N/A
Mean	160.215E-09	**StatLow**	N/A
StdDev	6.409E-09	**NWithinSpec**	N/A
25%	155.135E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	179.441E-09	**90%**	168.446E-09
		Range	25.703E-09
Mean-3*StdDev	140.989E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.015, Test.Name=232 RX4 SKEW



Statistics: (S)

Min	129.499E-09	**StatLow**	N/A
Max	194.708E-09	**NWithinSpec**	N/A
Mean	141.751E-09	**NOutsideSpec**	N/A
StdDev	9.846E-09	**90%**	149.246E-09
25%	138.684E-09	**Range**	65.209E-09
Mean+3*StdDev	171.289E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	112.214E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.3576		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

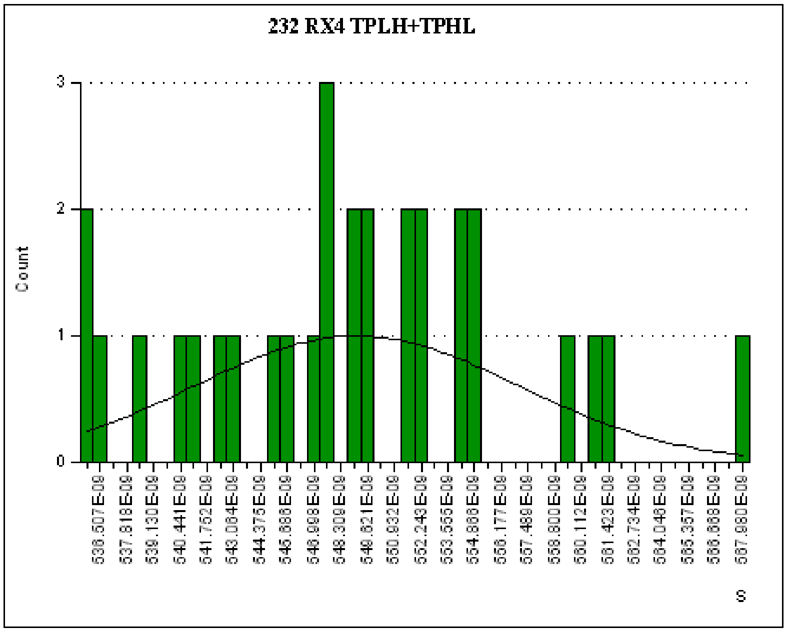
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.016, Test.Name=232 RX4 TPLH+TPHL



Statistics: (S)

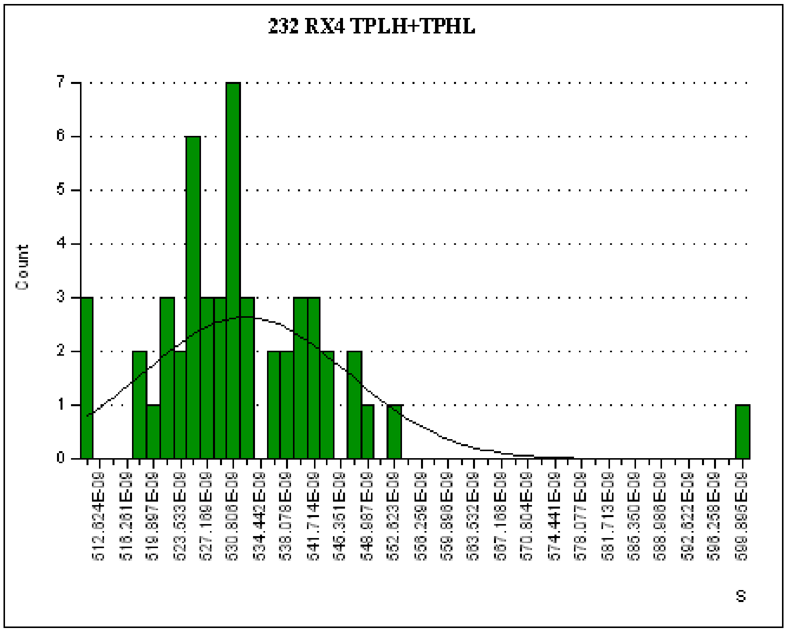
Min	535.851E-09	**Skew**	0.2744
Max	567.980E-09	**StatHigh**	N/A
Mean	548.947E-09	**StatLow**	N/A
StdDev	7.837E-09	**NWithinSpec**	N/A
25%	543.195E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	572.459E-09	**90%**	560.177E-09
		Range	32.129E-09
Mean-3*StdDev	525.436E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.016, Test.Name=232 RX4 TPLH+TPHL



Statistics: (S)

Min	510.806E-09	**StatLow**	N/A
Max	599.895E-09	**NWithinSpec**	N/A
Mean	532.132E-09	**NOutsideSpec**	N/A
StdDev	13.745E-09	**90%**	545.248E-09
25%	525.501E-09	**Range**	89.088E-09
Mean+3*StdDev	573.367E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	490.897E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	2.4064		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

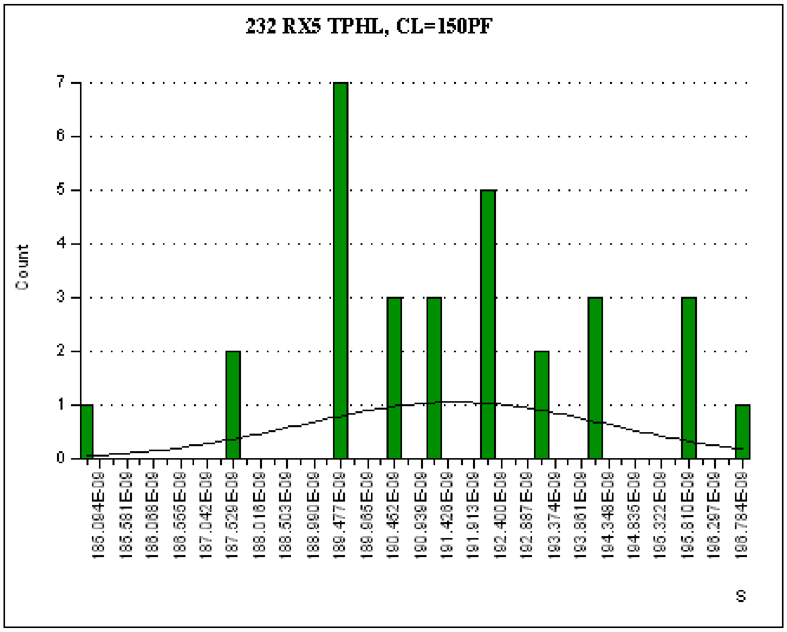
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.017, Test.Name=232 RX5 TPHL, CL=150PF



Statistics: (S)

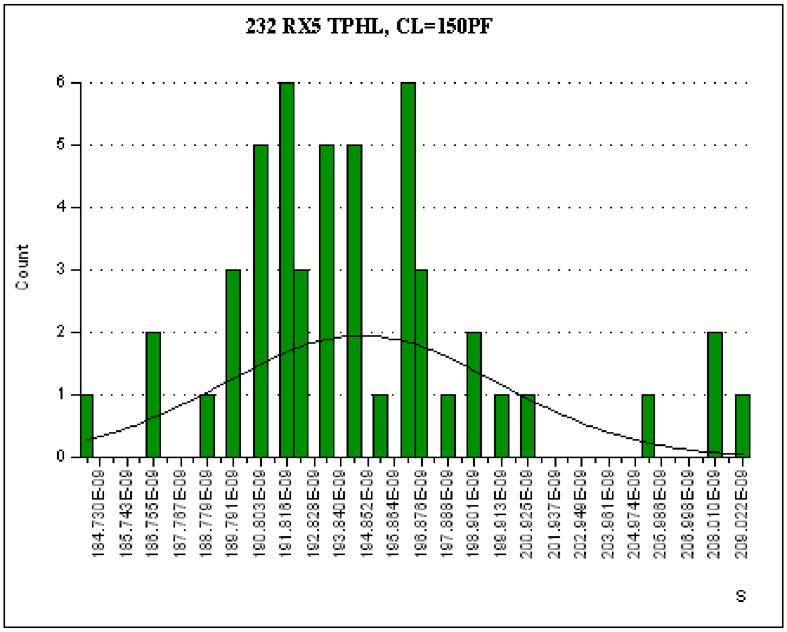
Min	184.850E-09	**Skew**	-0.0278
Max	196.784E-09	**StatHigh**	N/A
Mean	191.490E-09	**StatLow**	N/A
StdDev	2.756E-09	**NWithinSpec**	N/A
25%	189.440E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	199.758E-09	**90%**	195.866E-09
		Range	11.933E-09
Mean-3*StdDev	183.223E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.017, Test.Name=232 RX5 TPHL, CL=150PF



Statistics: (S)

Min	184.224E-09	**StatLow**	N/A
Max	209.022E-09	**NWithinSpec**	N/A
Mean	194.511E-09	**NOutsideSpec**	N/A
StdDev	5.186E-09	**90%**	200.297E-09
25%	191.572E-09	**Range**	24.798E-09
Mean+3*StdDev	210.067E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	178.954E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.0846		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

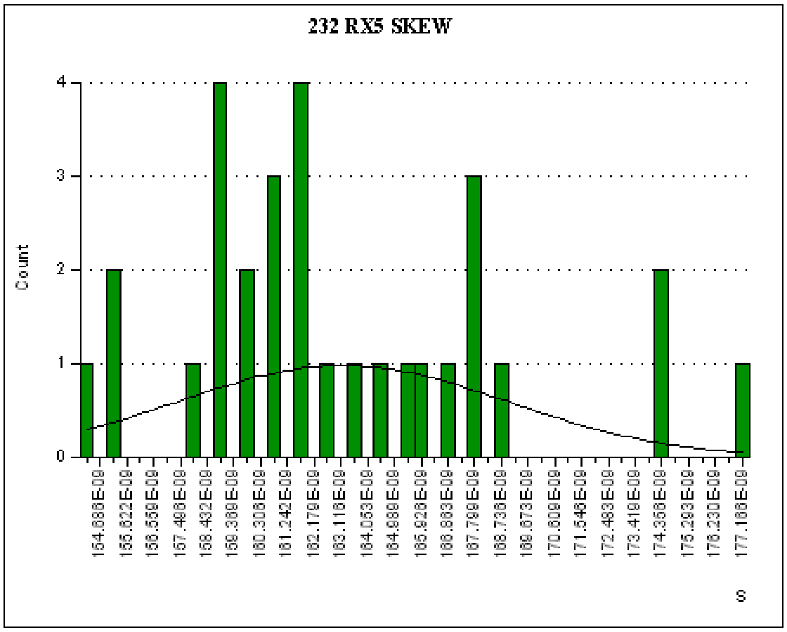
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.018, Test.Name=232 RX5 SKEW



Statistics: (S)

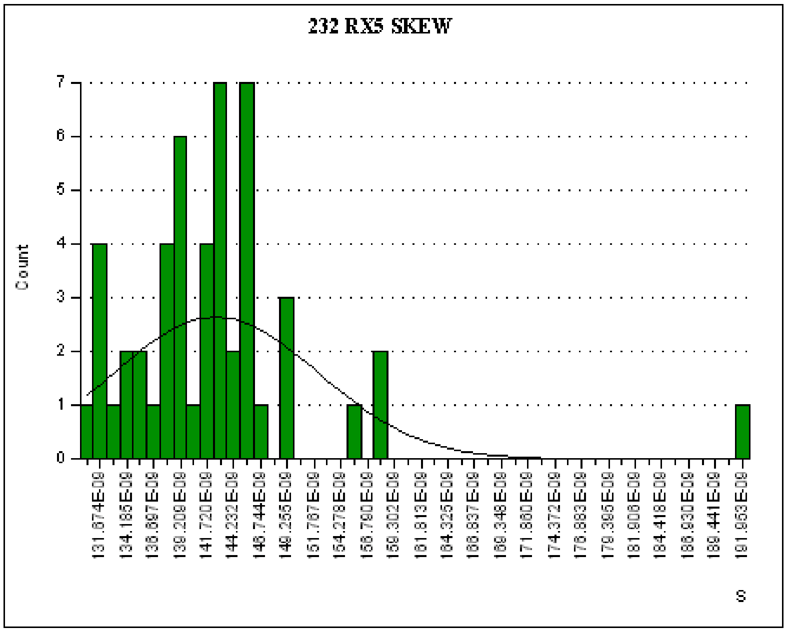
Min	154.217E-09	**Skew**	0.8003
Max	177.166E-09	**StatHigh**	N/A
Mean	163.091E-09	**StatLow**	N/A
StdDev	5.717E-09	**NWithinSpec**	N/A
25%	158.807E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	180.241E-09	**90%**	171.658E-09
		Range	22.949E-09
Mean-3*StdDev	145.941E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.018, Test.Name=232 RX5 SKEW



Statistics: (S)

Min	130.418E-09	**StatLow**	N/A
Max	191.953E-09	**NWithinSpec**	N/A
Mean	142.431E-09	**NOutsideSpec**	N/A
StdDev	9.512E-09	**90%**	148.787E-09
25%	137.765E-09	**Range**	61.535E-09
Mean+3*StdDev	170.967E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	113.895E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	3.0346		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

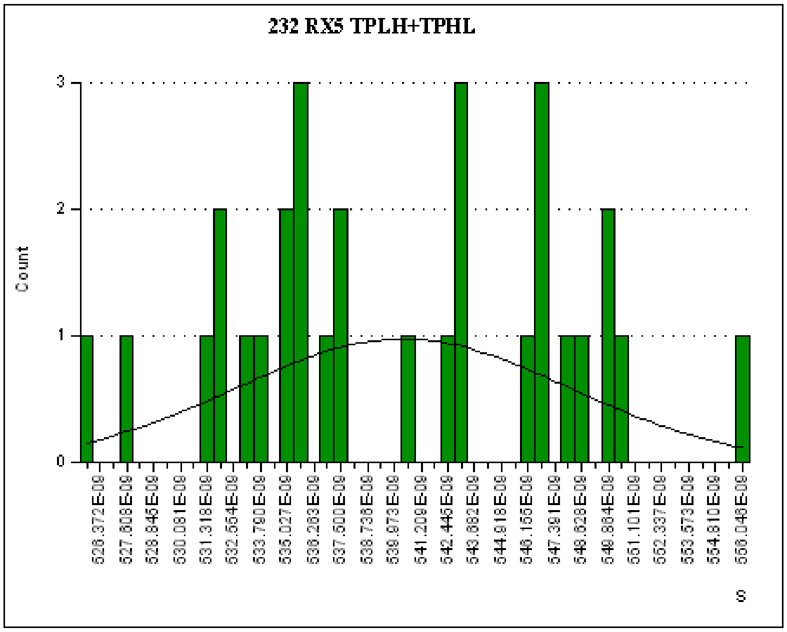
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=16.019, Test.Name=232 RX5 TPLH+TPHL



Statistics: (S)

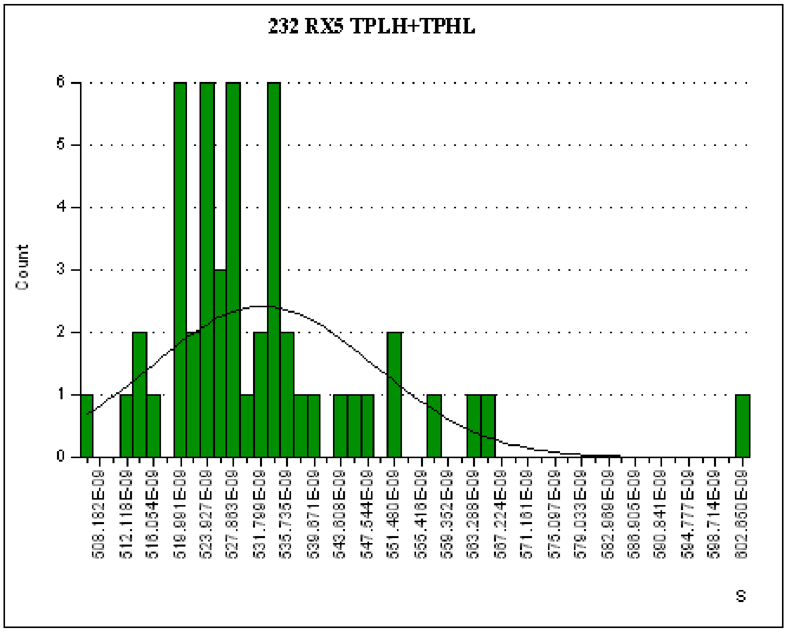
Min	525.754E-09	**Skew**	0.0739
Max	556.046E-09	**StatHigh**	N/A
Mean	540.227E-09	**StatLow**	N/A
StdDev	7.576E-09	**NWithinSpec**	N/A
25%	534.933E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	562.955E-09	**90%**	549.621E-09
		Range	30.293E-09
Mean-3*StdDev	517.498E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=16.019, Test.Name=232 RX5 TPLH+TPHL



Statistics: (S)

Min	506.214E-09	**StatLow**	N/A
Max	602.650E-09	**NWithinSpec**	N/A
Mean	531.894E-09	**NOutsideSpec**	N/A
StdDev	16.247E-09	**90%**	552.136E-09
25%	522.746E-09	**Range**	96.436E-09
Mean+3*StdDev	580.635E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	483.152E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.0414		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

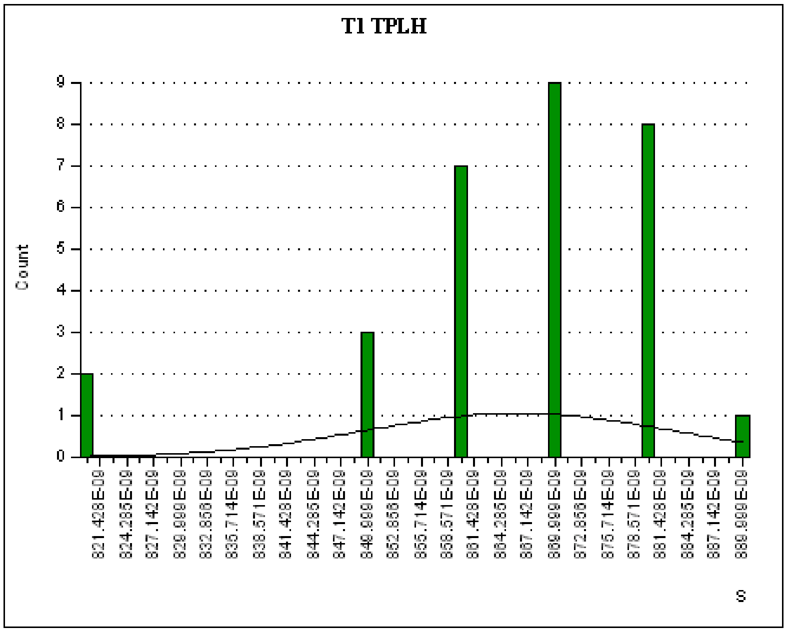
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=17.000, Test.Name=T1 TPLH



Statistics: (S)

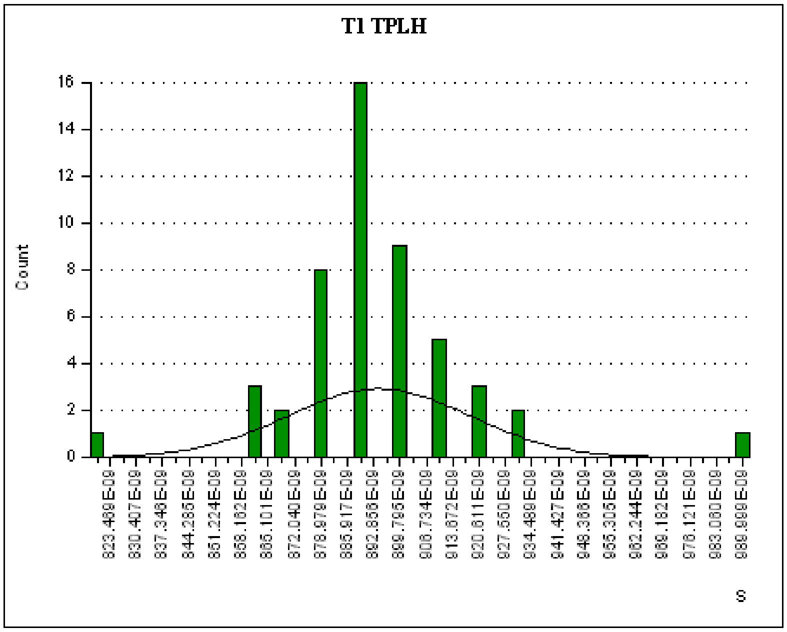
Min	819.999E-09	**Skew**	-1.4514
Max	889.999E-09	**StatHigh**	N/A
Mean	865.666E-09	**StatLow**	N/A
StdDev	16.121E-09	**NWithinSpec**	N/A
25%	859.999E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	914.029E-09	**90%**	879.999E-09
		Range	70.000E-09
Mean-3*StdDev	817.303E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.000, Test.Name=T1 TPLH



Statistics: (S)

Min	819.999E-09	**StatLow**	N/A
Max	989.999E-09	**NWithinSpec**	N/A
Mean	893.599E-09	**NOutsideSpec**	N/A
StdDev	23.626E-09	**90%**	919.999E-09
25%	879.999E-09	**Range**	169.999E-09
Mean+3*StdDev	964.478E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	822.720E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.8257		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

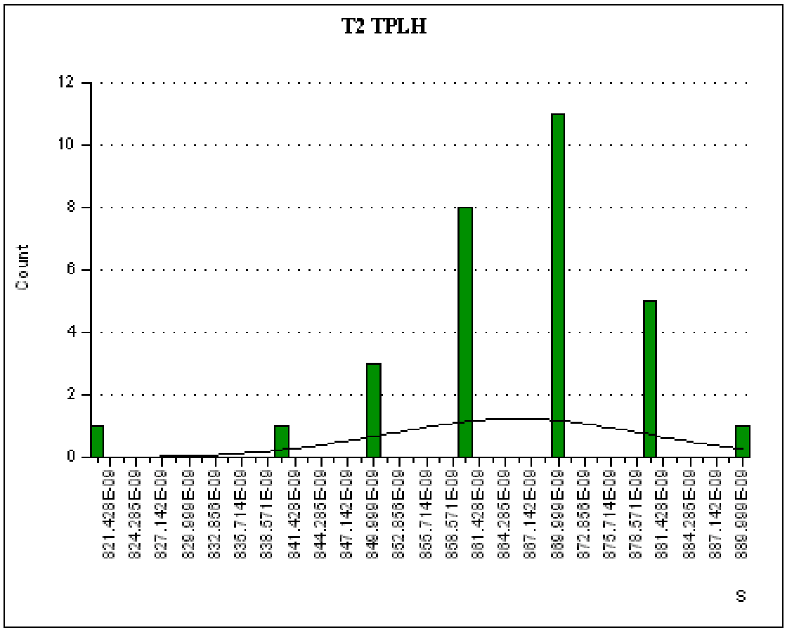
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=17.001, Test.Name=T2 TPLH



Statistics: (S)

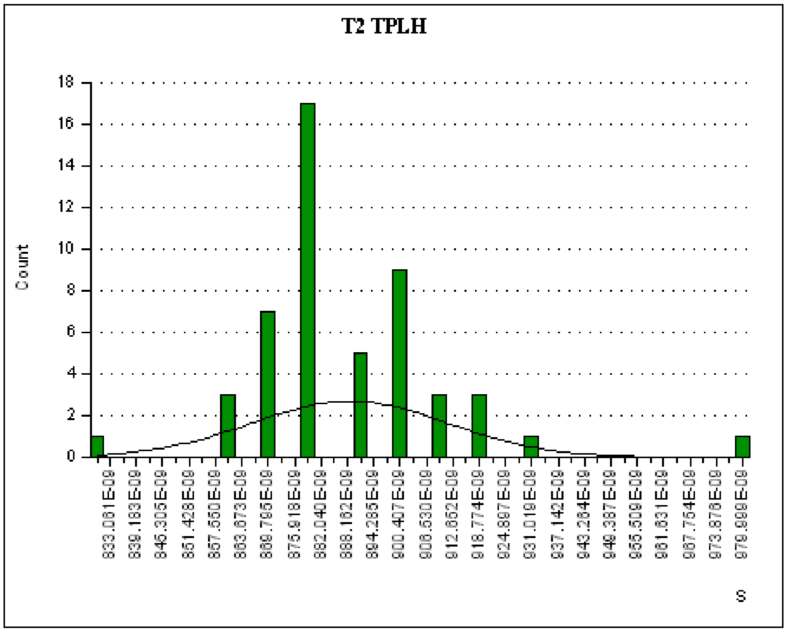
Min	819.999E-09	**Skew**	-1.1722
Max	889.999E-09	**StatHigh**	N/A
Mean	864.999E-09	**StatLow**	N/A
StdDev	13.834E-09	**NWithinSpec**	N/A
25%	859.999E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	906.501E-09	**90%**	879.999E-09
		Range	70.000E-09
Mean-3*StdDev	823.497E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.001, Test.Name=T2 TPLH



Statistics: (S)

Min	829.999E-09	**StatLow**	N/A
Max	979.999E-09	**NWithinSpec**	N/A
Mean	888.199E-09	**NOutsideSpec**	N/A
StdDev	22.650E-09	**90%**	914.999E-09
25%	879.999E-09	**Range**	149.999E-09
Mean+3*StdDev	956.149E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	820.250E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.2313		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

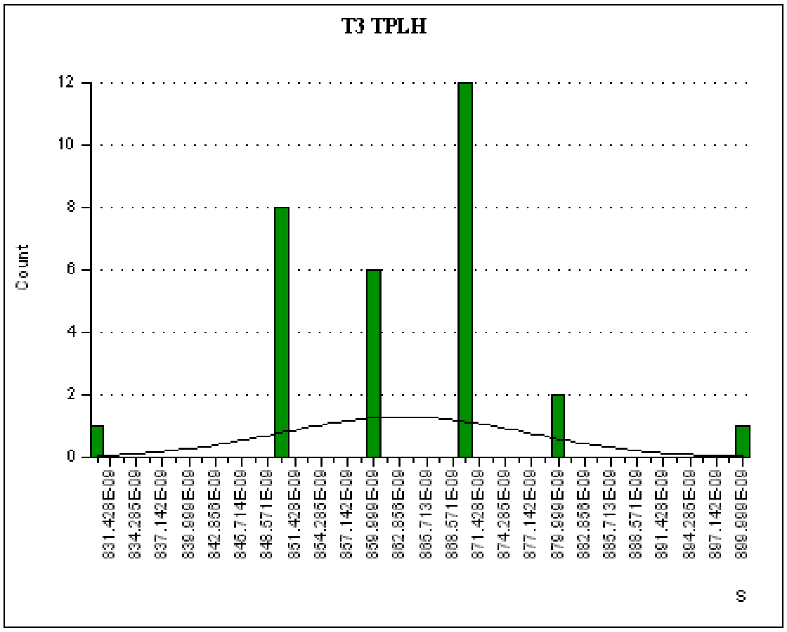
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=17.002, Test.Name=T3 TPLH



Statistics: (S)

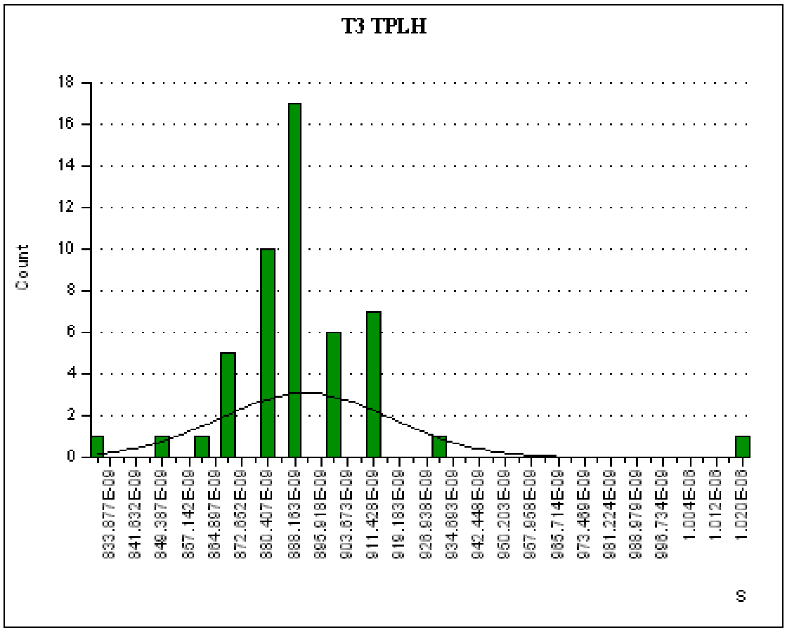
Min	829.999E-09	**Skew**	0.1766
Max	899.999E-09	**StatHigh**	N/A
Mean	862.999E-09	**StatLow**	N/A
StdDev	13.170E-09	**NWithinSpec**	N/A
25%	849.999E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	902.509E-09	**90%**	874.999E-09
		Range	70.000E-09
Mean-3*StdDev	823.489E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.002, Test.Name=T3 TPLH



Statistics: (S)

Min	829.999E-09	**StatLow**	N/A
Max	1.020E-06	**NWithinSpec**	N/A
Mean	890.799E-09	**NOutsideSpec**	N/A
StdDev	25.140E-09	**90%**	909.999E-09
25%	879.999E-09	**Range**	190.000E-09
Mean+3*StdDev	966.218E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	815.380E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.5310		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

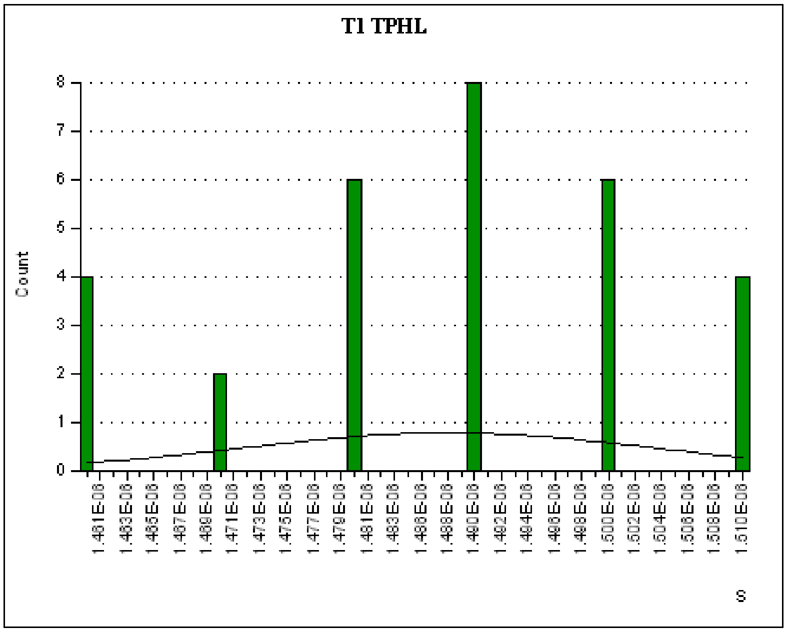
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=17.003, Test.Name=T1 TPHL



Statistics: (S)

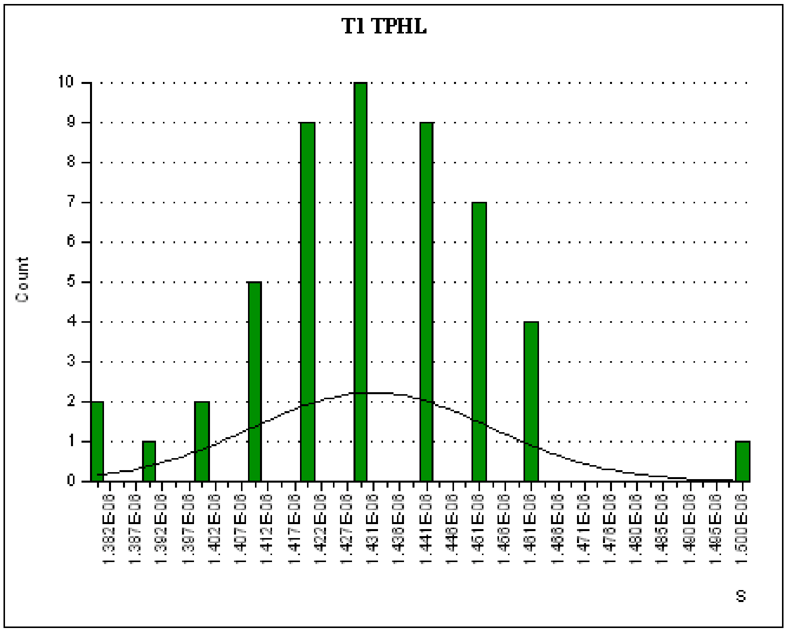
Min	1.460E-06	**Skew**	-0.3511
Max	1.510E-06	**StatHigh**	N/A
Mean	1.487E-06	**StatLow**	N/A
StdDev	15.522E-09	**NWithinSpec**	N/A
25%	1.480E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.534E-06	**90%**	1.510E-06
		Range	50.000E-09
Mean-3*StdDev	1.441E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.003, Test.Name=T1 TPHL



Statistics: (S)

Min	1.380E-06	**StatLow**	N/A
Max	1.500E-06	**NWithinSpec**	N/A
Mean	1.431E-06	**NOutsideSpec**	N/A
StdDev	21.891E-09	**90%**	1.455E-06
25%	1.420E-06	**Range**	120.001E-09
Mean+3*StdDev	1.496E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.365E-06	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.1149		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

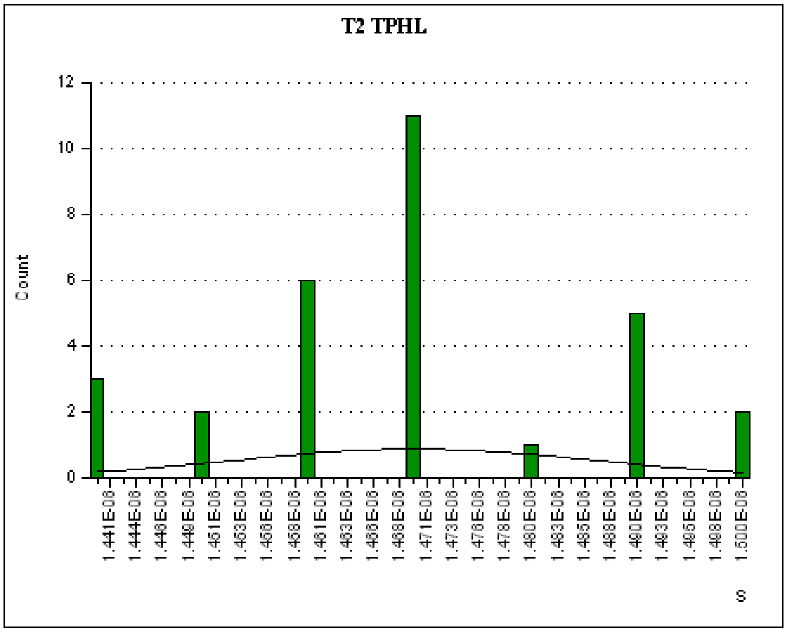
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=17.005, Test.Name=T2 TPHL



Statistics: (S)

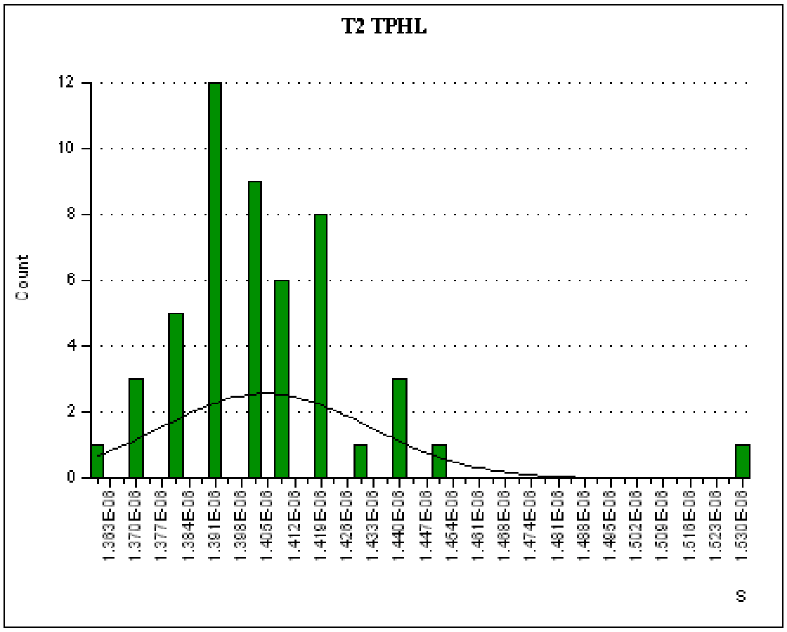
Min	1.440E-06	**Skew**	0.0646
Max	1.500E-06	**StatHigh**	N/A
Mean	1.469E-06	**StatLow**	N/A
StdDev	16.595E-09	**NWithinSpec**	N/A
25%	1.460E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.519E-06	**90%**	1.490E-06
Mean-3*StdDev	1.420E-06	**Range**	60.000E-09
Cpk	N/A	**NOutsideSpec**	N/A

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.005, Test.Name=T2 TPHL



Statistics: (S)

Min	1.360E-06	**StatLow**	N/A
Max	1.530E-06	**NWithinSpec**	N/A
Mean	1.404E-06	**NOutsideSpec**	N/A
StdDev	26.954E-09	**90%**	1.435E-06
25%	1.390E-06	**Range**	170.000E-09
Mean+3*StdDev	1.485E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.323E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.1533		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

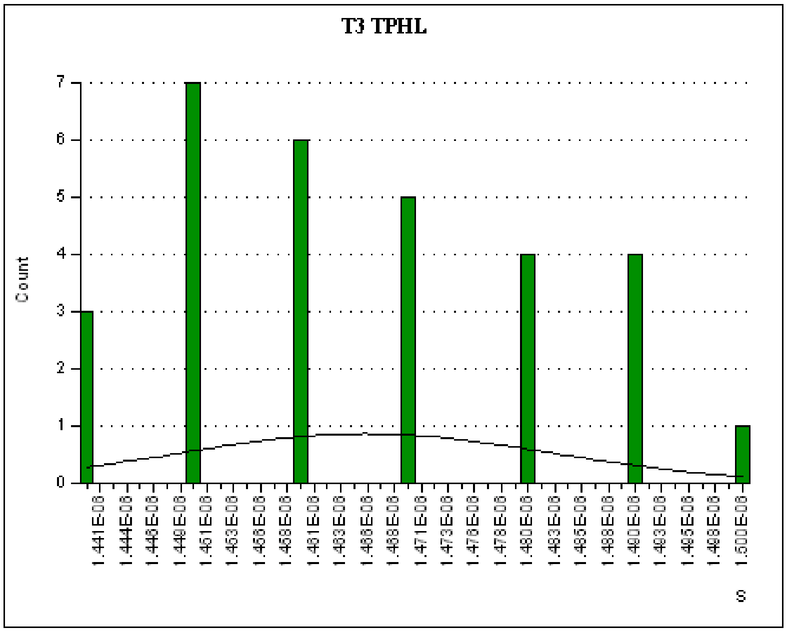
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=17.007, Test.Name=T3 TPHL



Statistics: (S)

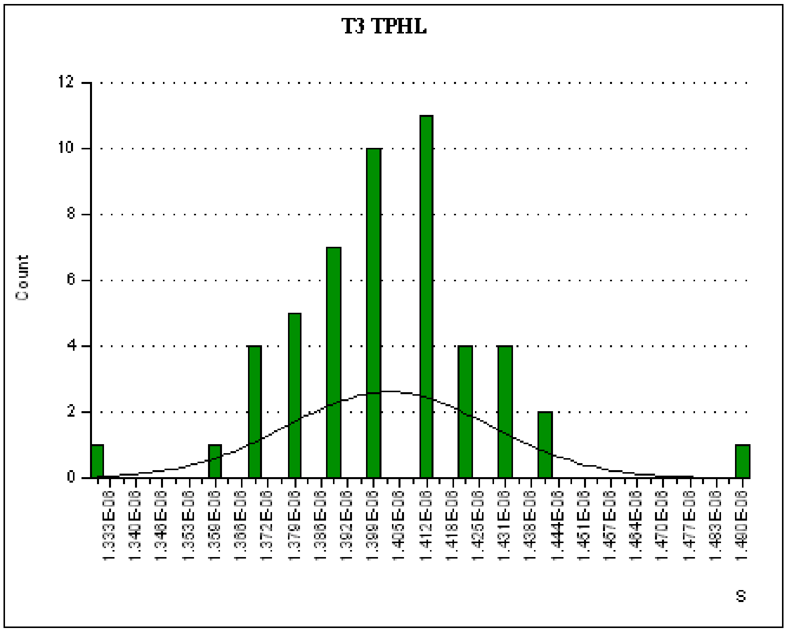
Min	1.440E-06	**Skew**	0.3019
Max	1.500E-06	**StatHigh**	N/A
Mean	1.465E-06	**StatLow**	N/A
StdDev	16.965E-09	**NWithinSpec**	N/A
25%	1.450E-06	**NOutsideSpec**	N/A
Mean+3*StdDev	1.516E-06	**90%**	1.490E-06
		Range	60.000E-09
Mean-3*StdDev	1.414E-06	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=17.007, Test.Name=T3 TPHL



Statistics: (S)

Min	1.330E-06	**StatLow**	N/A
Max	1.490E-06	**NWithinSpec**	N/A
Mean	1.402E-06	**NOutsideSpec**	N/A
StdDev	24.856E-09	**90%**	1.430E-06
25%	1.390E-06	**Range**	160.000E-09
Mean+3*StdDev	1.476E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.327E-06	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.4160		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

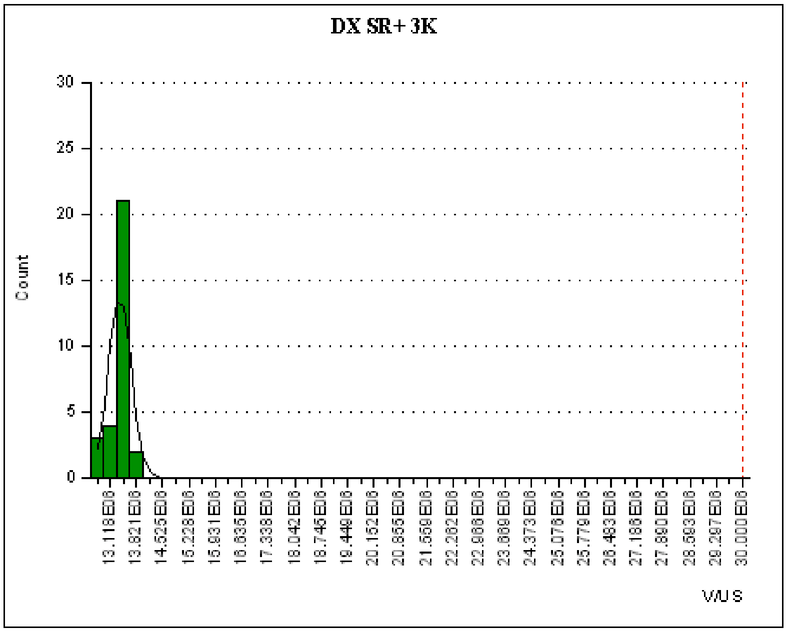
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=18.000, Test.Name=DX SR+ 3K



Statistics: (V/US)

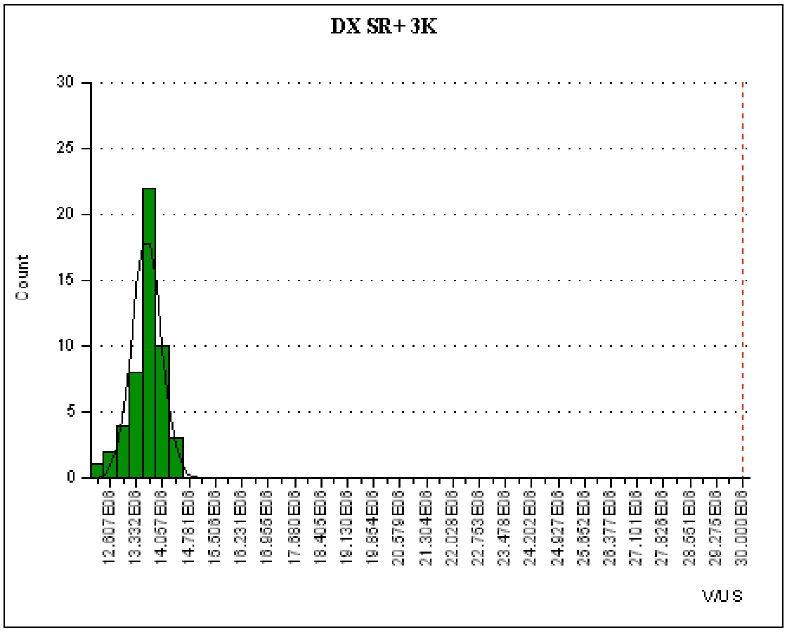
Min	12.766E06	**Skew**	-0.1413
Max	13.954E06	**StatHigh**	N/A
Mean	13.350E06	**StatLow**	N/A
StdDev	305.437E03	**NWithinSpec**	30
25%	13.333E06	**NOutsideSpec**	0
Mean+3*StdDev	14.266E06	**90%**	13.636E06
		Range	1.188E06
Mean-3*StdDev	12.434E06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=18.000, Test.Name=DX SR+ 3K



Statistics: (V/US)

Min	12.245E06	**StatLow**	N/A
Max	14.286E06	**NWithinSpec**	50
Mean	13.580E06	**NOutsideSpec**	0
StdDev	396.540E03	**90%**	13.954E06
25%	13.333E06	**Range**	2.041E06
Mean+3*StdDev	14.770E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	12.391E06	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.8938		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

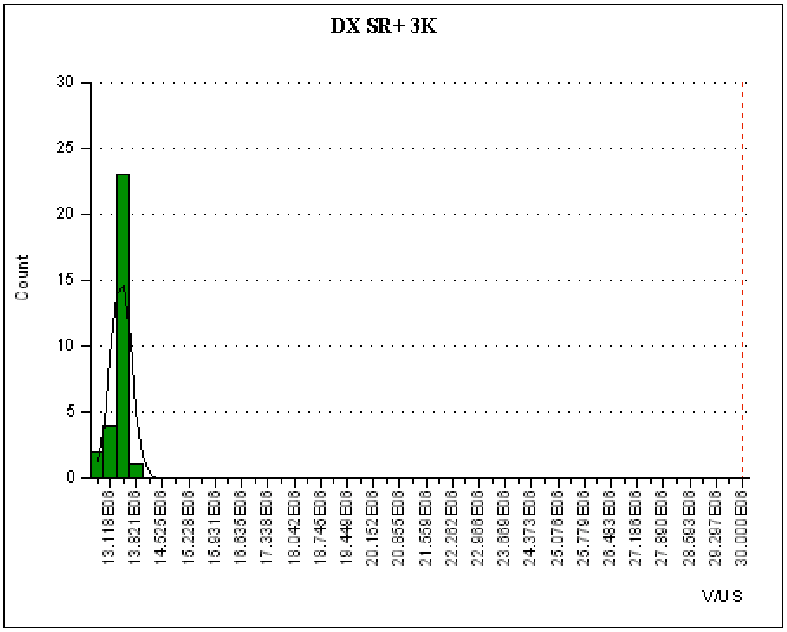
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=18.001, Test.Name=DX SR+ 3K



Statistics: (V/US)

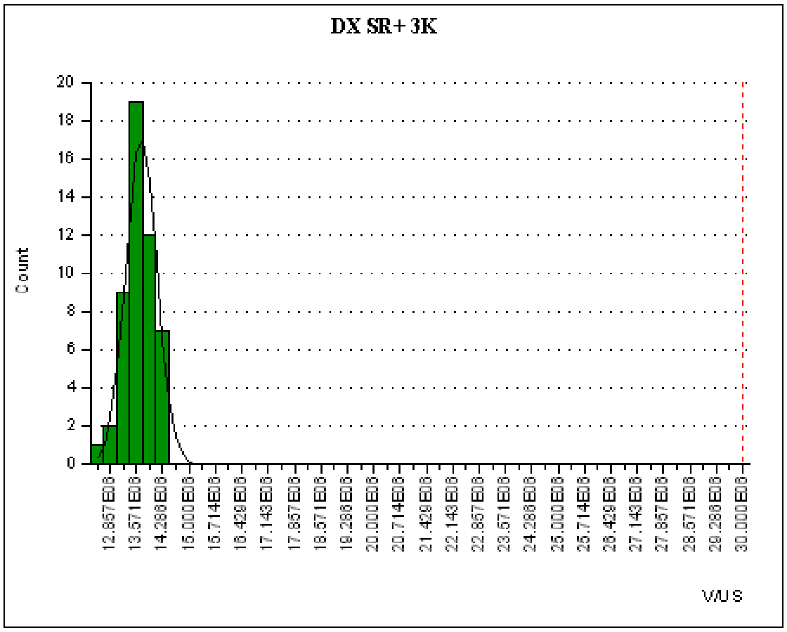
Min	12.766E06	**Skew**	-0.5052
Max	13.954E06	**StatHigh**	N/A
Mean	13.389E06	**StatLow**	N/A
StdDev	280.567E03	**NWithinSpec**	30
25%	13.333E06	**NOutsideSpec**	0
Mean+3*StdDev	14.230E06	**90%**	13.636E06
		Range	1.188E06
Mean-3*StdDev	12.547E06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=18.001, Test.Name=DX SR+ 3K



Statistics: (V/US)

Min	12.500E06	**StatLow**	N/A
Max	14.286E06	**NWithinSpec**	50
Mean	13.674E06	**NOutsideSpec**	0
StdDev	416.497E03	**90%**	14.286E06
25%	13.636E06	**Range**	1.786E06
Mean+3*StdDev	14.923E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	12.424E06	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.6588		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

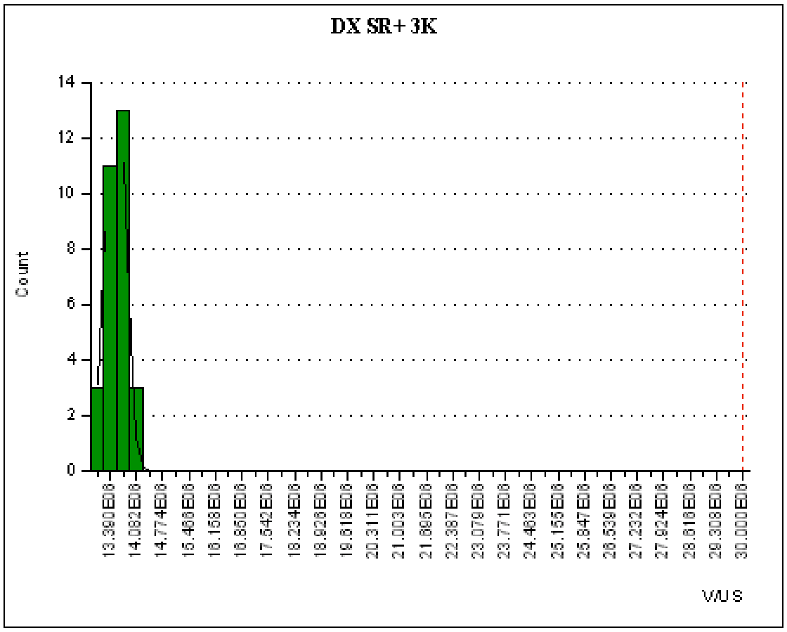
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=18.002, Test.Name=DX SR+ 3K



Statistics: (V/US)

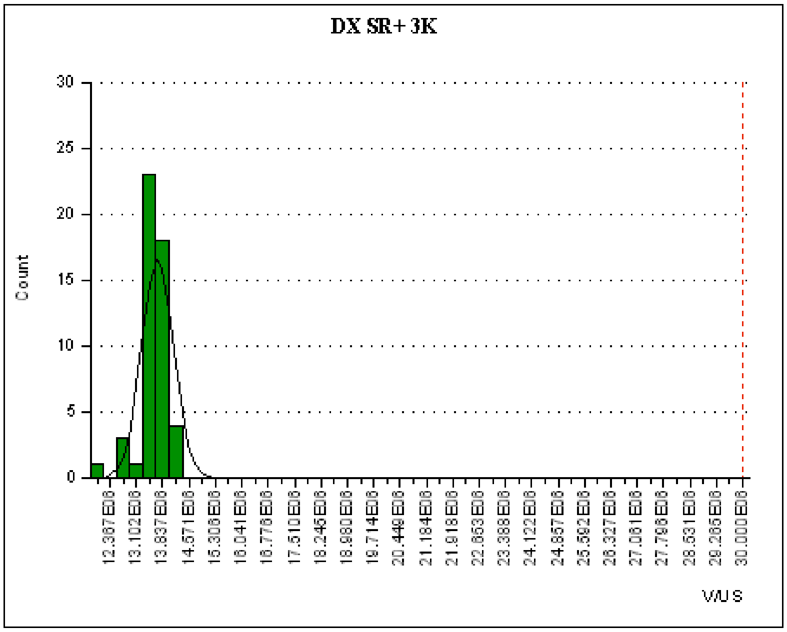
Min	13.043E06	**Skew**	-0.0269
Max	13.954E06	**StatHigh**	N/A
Mean	13.498E06	**StatLow**	N/A
StdDev	248.397E03	**NWithinSpec**	30
25%	13.333E06	**NOutsideSpec**	0
Mean+3*StdDev	14.243E06	**90%**	13.795E06
		Range	910.011E03
Mean-3*StdDev	12.752E06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=18.002, Test.Name=DX SR+ 3K



Statistics: (V/US)

Min	12.000E06	**StatLow**	N/A
Max	14.286E06	**NWithinSpec**	50
Mean	13.657E06	**NOutsideSpec**	0
StdDev	440.590E03	**90%**	13.954E06
25%	13.333E06	**Range**	2.286E06
Mean+3*StdDev	14.979E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	12.335E06	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-1.4208		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

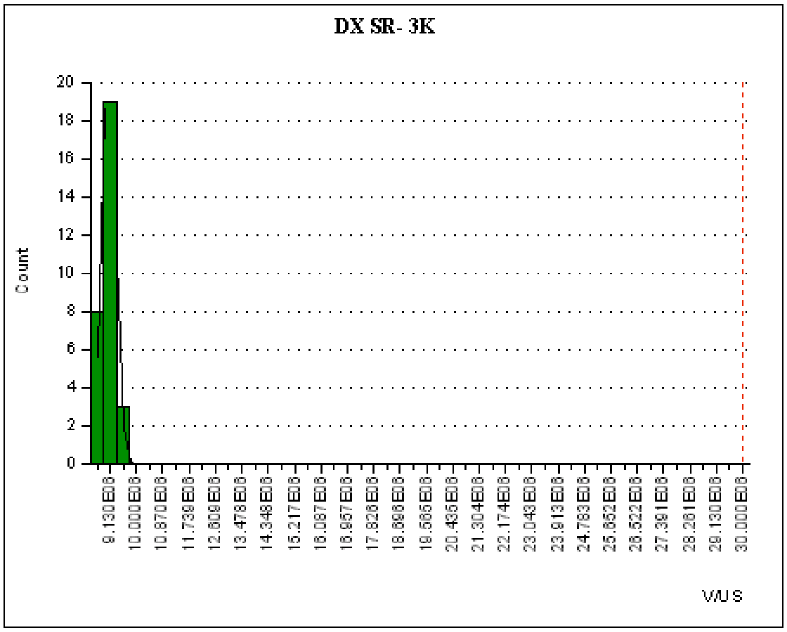
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=18.003, Test.Name=DX SR- 3K



Statistics: (V/US)

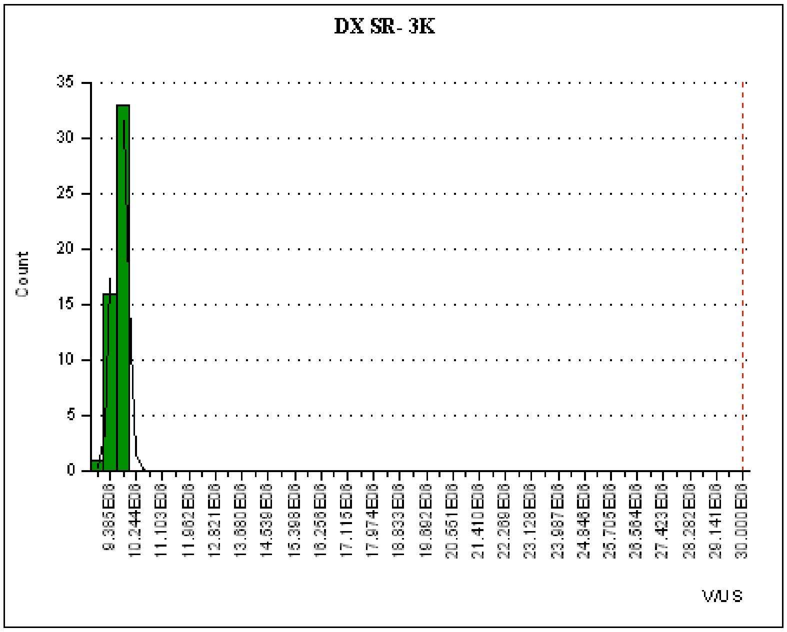
Min	8.696E06	**Skew**	-0.4647
Max	9.375E06	**StatHigh**	N/A
Mean	9.064E06	**StatLow**	N/A
StdDev	215.275E03	**NWithinSpec**	30
25%	8.824E06	**NOutsideSpec**	0
Mean+3*StdDev	9.710E06	**90%**	9.303E06
		Range	679.348E03
Mean-3*StdDev	8.418E06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=18.003, Test.Name=DX SR- 3K



Statistics: (V/US)

Min	8.955E06	**StatLow**	N/A
Max	10.000E06	**NWithinSpec**	50
Mean	9.658E06	**NOutsideSpec**	0
StdDev	222.837E03	**90%**	9.918E06
25%	9.524E06	**Range**	1.045E06
Mean+3*StdDev	10.326E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	8.989E06	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.7737		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

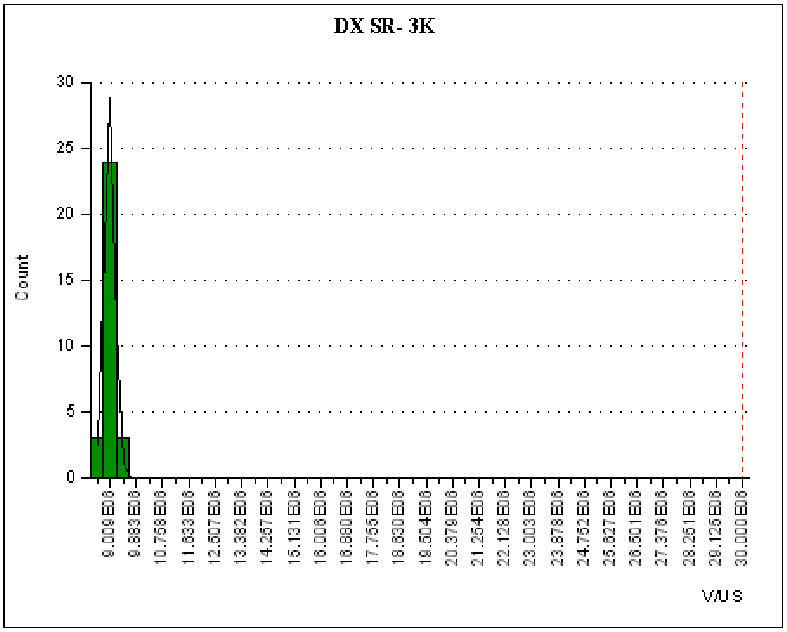
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=18.004, Test.Name=DX SR- 3K



Statistics: (V/US)

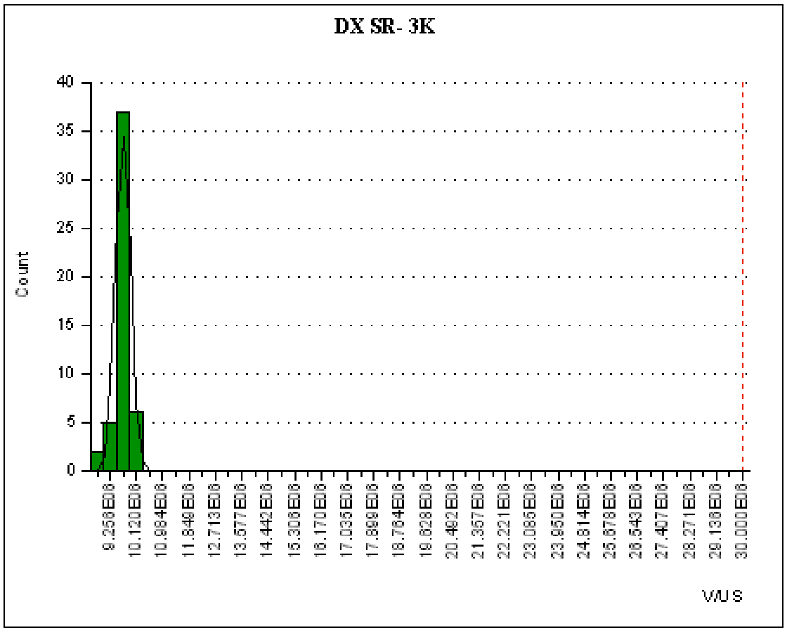
Min	8.571E06	**Skew**	-0.0227
Max	9.375E06	**StatHigh**	N/A
Mean	8.968E06	**StatLow**	N/A
StdDev	178.922E03	**NWithinSpec**	30
25%	8.824E06	**NOutsideSpec**	0
Mean+3*StdDev	9.504E06	**90%**	9.161E06
		Range	803.572E03
Mean-3*StdDev	8.431E06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=18.004, Test.Name=DX SR- 3K



Statistics: (V/US)

Min	8.824E06	**StatLow**	N/A
Max	10.000E06	**NWithinSpec**	50
Mean	9.653E06	**NOutsideSpec**	0
StdDev	249.243E03	**90%**	10.000E06
25%	9.524E06	**Range**	1.176E06
Mean+3*StdDev	10.401E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	8.905E06	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-1.0533		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

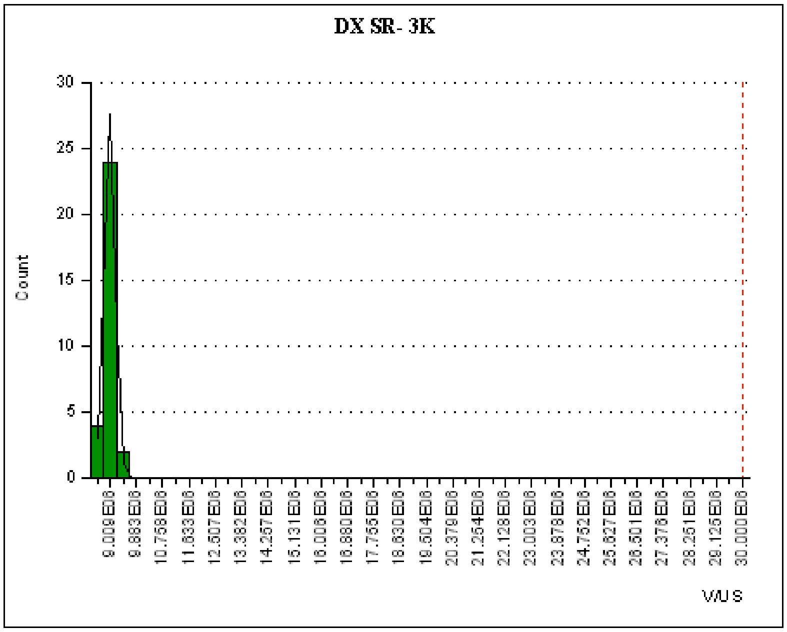
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=18.005, Test.Name=DX SR- 3K



Statistics: (V/US)

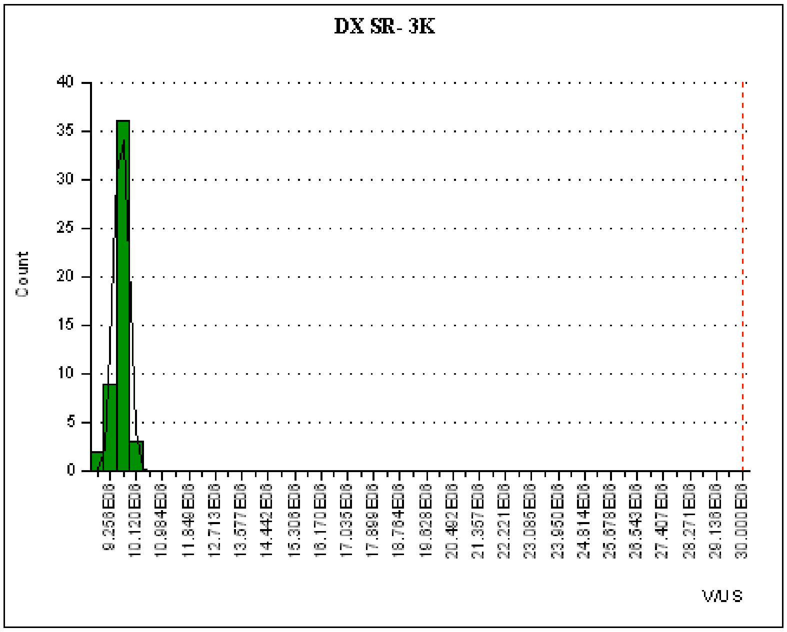
Min	8.571E06	**Skew**	-0.3535
Max	9.375E06	**StatHigh**	N/A
Mean	8.963E06	**StatLow**	N/A
StdDev	186.108E03	**NWithinSpec**	30
25%	8.824E06	**NOutsideSpec**	0
Mean+3*StdDev	9.522E06	**90%**	9.091E06
		Range	803.572E03
Mean-3*StdDev	8.405E06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=18.005, Test.Name=DX SR- 3K



Statistics: (V/US)

Min	8.824E06	**StatLow**	N/A
Max	10.000E06	**NWithinSpec**	50
Mean	9.594E06	**NOutsideSpec**	0
StdDev	239.941E03	**90%**	9.836E06
25%	9.524E06	**Range**	1.176E06
Mean+3*StdDev	10.314E06	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	8.874E06	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-0.9271		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

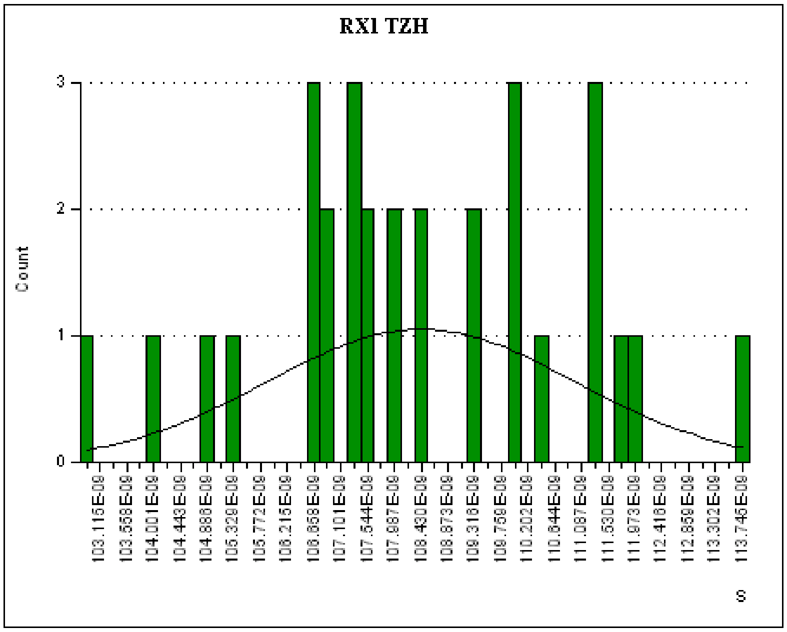
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.000, Test.Name=RX1 TZH



Statistics: (S)

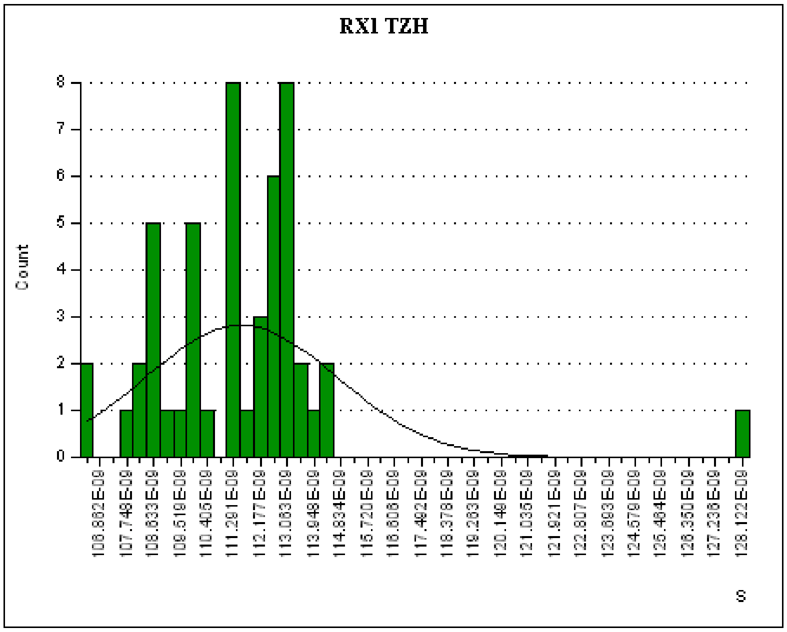
Min	102.893E-09	**Skew**	-0.0148
Max	113.745E-09	**StatHigh**	N/A
Mean	108.376E-09	**StatLow**	N/A
StdDev	2.517E-09	**NWithinSpec**	N/A
25%	106.963E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	115.928E-09	**90%**	111.541E-09
		Range	10.852E-09
Mean-3*StdDev	100.823E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.000, Test.Name=RX1 TZH



Statistics: (S)

Min	106.419E-09	**StatLow**	N/A
Max	128.122E-09	**NWithinSpec**	N/A
Mean	111.478E-09	**NOutsideSpec**	N/A
StdDev	3.138E-09	**90%**	113.540E-09
25%	109.810E-09	**Range**	21.703E-09
Mean+3*StdDev	120.892E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	102.064E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.8769		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

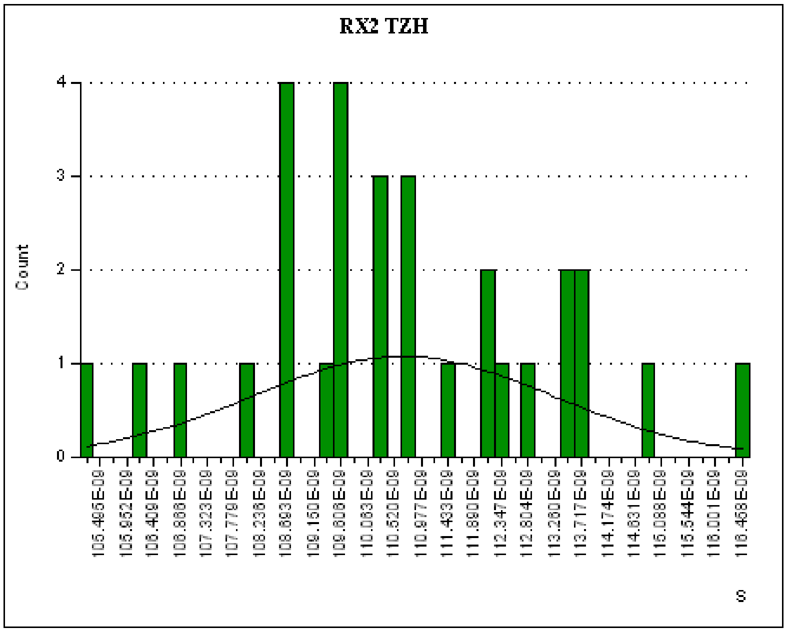
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.001, Test.Name=RX2 TZH



Statistics: (S)

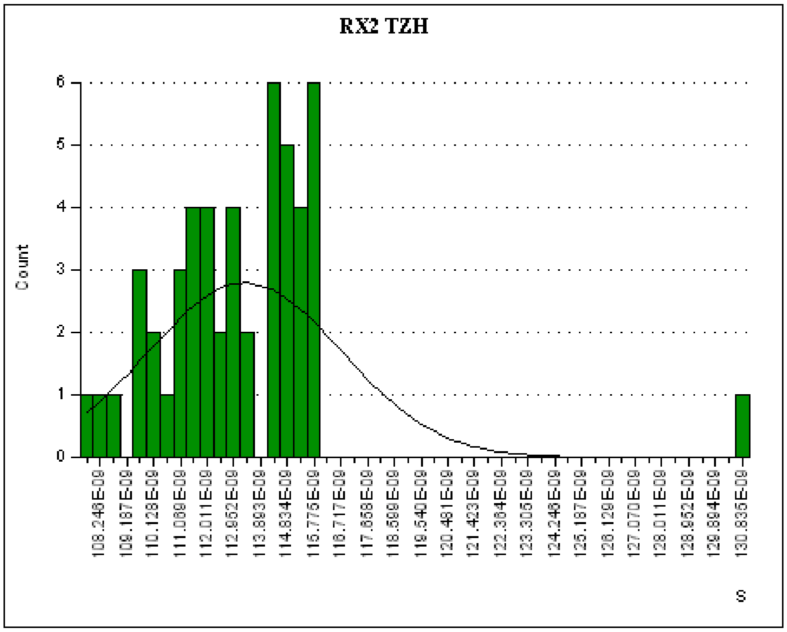
Min	105.267E-09	**Skew**	0.1375
Max	116.458E-09	**StatHigh**	N/A
Mean	110.614E-09	**StatLow**	N/A
StdDev	2.540E-09	**NWithinSpec**	N/A
25%	108.658E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	118.235E-09	**90%**	113.745E-09
		Range	11.191E-09
Mean-3*StdDev	102.993E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.001, Test.Name=RX2 TZH



Statistics: (S)

Min	107.775E-09	**StatLow**	N/A
Max	130.835E-09	**NWithinSpec**	N/A
Mean	113.276E-09	**NOutsideSpec**	N/A
StdDev	3.362E-09	**90%**	115.744E-09
25%	111.505E-09	**Range**	23.060E-09
Mean+3*StdDev	123.362E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	103.189E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	2.7581		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

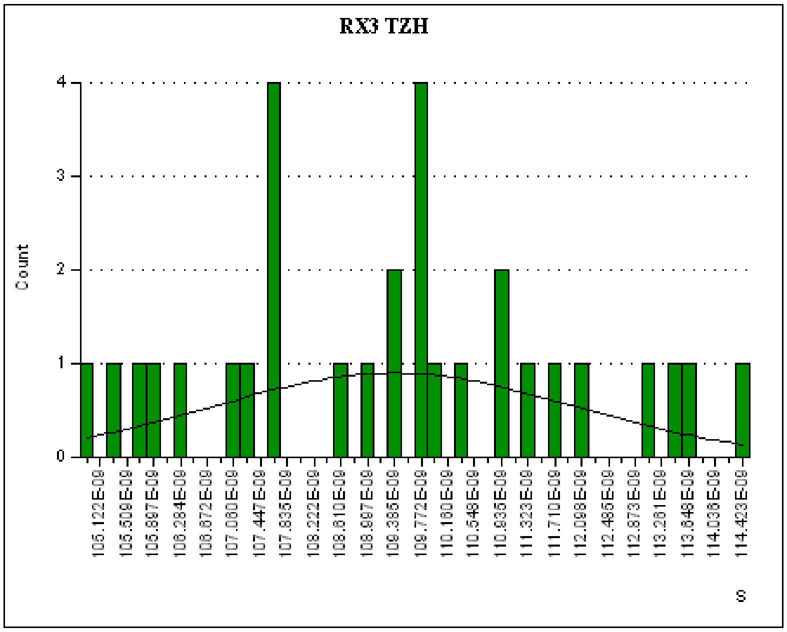
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.002, Test.Name=RX3 TZH



Statistics: (S)

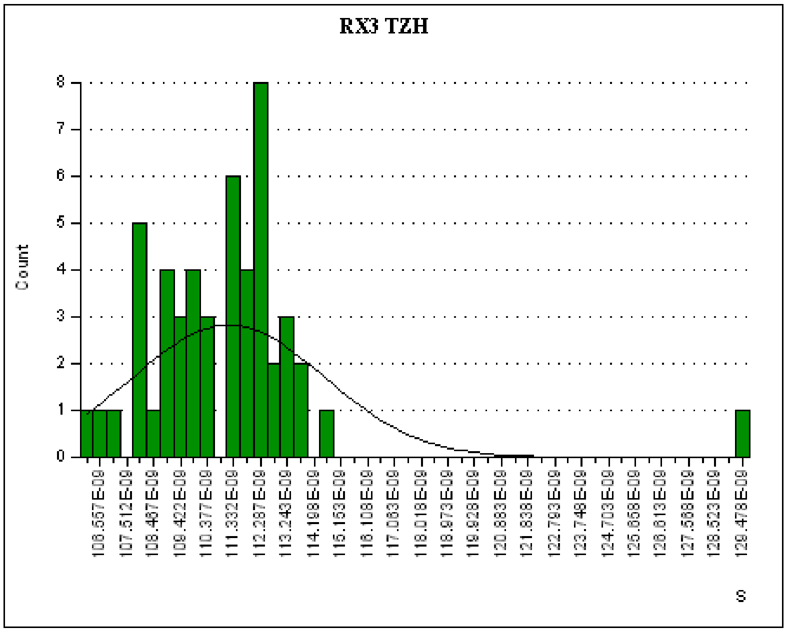
Min	104.928E-09	**Skew**	0.1624
Max	114.423E-09	**StatHigh**	N/A
Mean	109.336E-09	**StatLow**	N/A
StdDev	2.581E-09	**NWithinSpec**	N/A
25%	107.641E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	117.080E-09	**90%**	113.236E-09
		Range	9.495E-09
Mean-3*StdDev	101.593E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.002, Test.Name=RX3 TZH



Statistics: (S)

Min	106.080E-09	**StatLow**	N/A
Max	129.478E-09	**NWithinSpec**	N/A
Mean	111.098E-09	**NOutsideSpec**	N/A
StdDev	3.365E-09	**90%**	113.201E-09
25%	108.793E-09	**Range**	23.399E-09
Mean+3*StdDev	121.193E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	101.004E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	3.2553		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

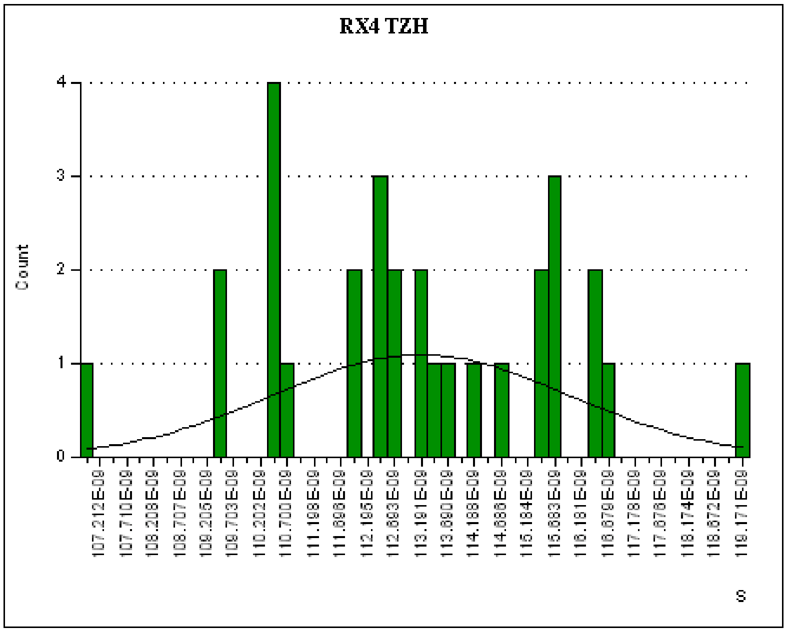
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.003, Test.Name=RX4 TZH



Statistics: (S)

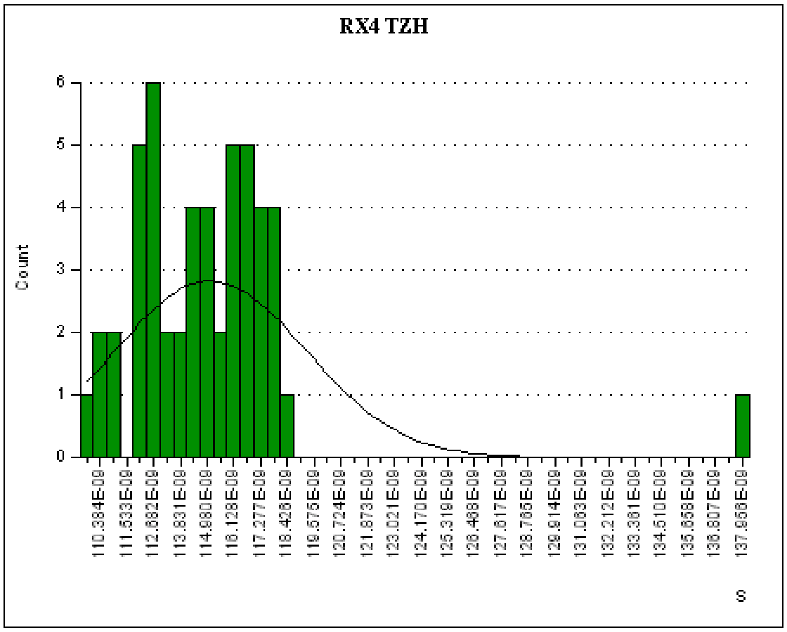
Min	106.963E-09	**Skew**	-0.0254
Max	119.171E-09	**StatHigh**	N/A
Mean	113.123E-09	**StatLow**	N/A
StdDev	2.728E-09	**NWithinSpec**	N/A
25%	110.693E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	121.306E-09	**90%**	116.458E-09
		Range	12.208E-09
Mean-3*StdDev	104.940E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.003, Test.Name=RX4 TZH



Statistics: (S)

Min	109.810E-09	**StatLow**	N/A
Max	137.956E-09	**NWithinSpec**	N/A
Mean	115.053E-09	**NOutsideSpec**	N/A
StdDev	4.053E-09	**90%**	117.609E-09
25%	112.523E-09	**Range**	28.146E-09
Mean+3*StdDev	127.211E-09	**NOutsideSpec**	N/A
Mean-3*StdDev	102.894E-09	**Cp**	N/A
Cpk	N/A	**Cpl**	N/A
Skew	3.6581	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

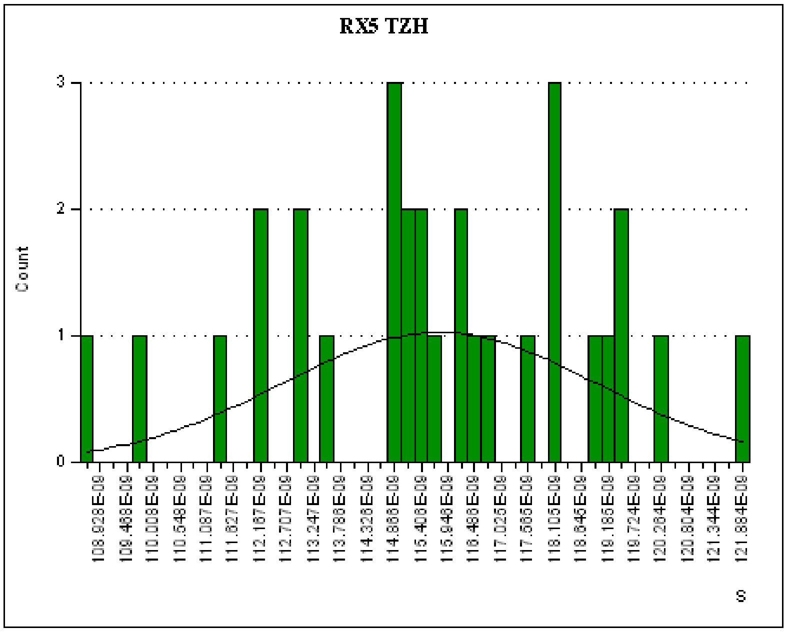
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.004, Test.Name=RX5 TZH



Statistics: (S)

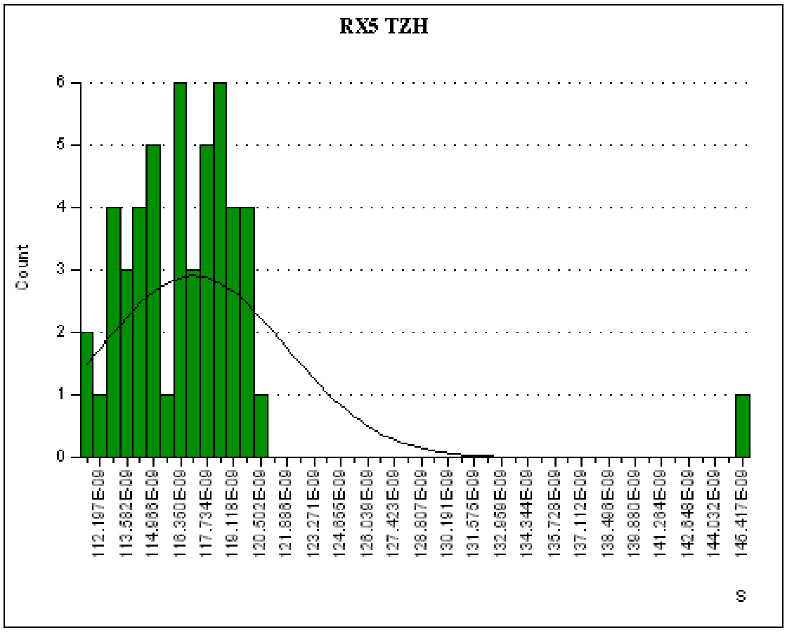
Min	108.658E-09	**Skew**	-0.2813
Max	121.884E-09	**StatHigh**	N/A
Mean	115.701E-09	**StatLow**	N/A
StdDev	3.143E-09	**NWithinSpec**	N/A
25%	113.406E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	125.130E-09	**90%**	119.510E-09
		Range	13.225E-09
Mean-3*StdDev	106.271E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.004, Test.Name=RX5 TZH



Statistics: (S)

Min	111.505E-09	**StatLow**	N/A
Max	145.417E-09	**NWithinSpec**	N/A
Mean	116.965E-09	**NOutsideSpec**	N/A
StdDev	4.751E-09	**90%**	119.644E-09
25%	114.218E-09	**Range**	33.911E-09
Mean+3*StdDev	131.219E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	102.712E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	4.4385		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

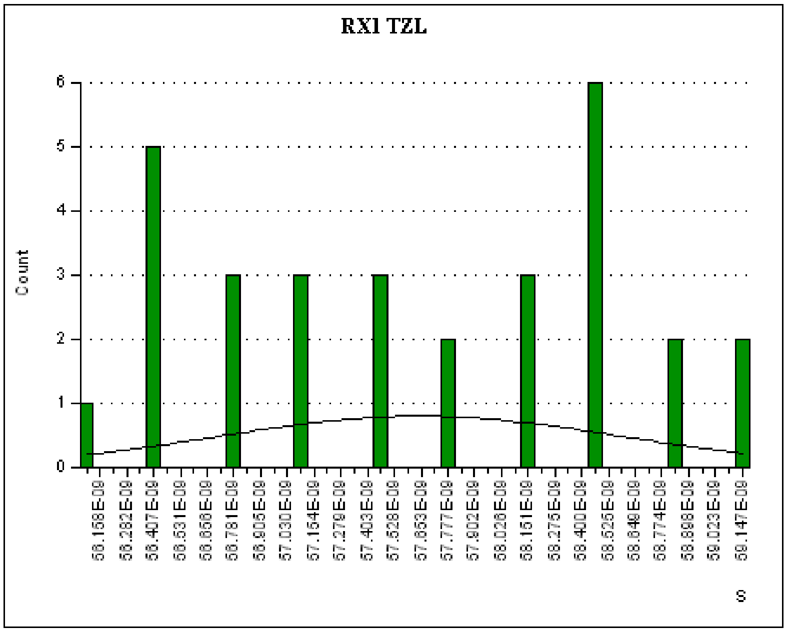
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.005, Test.Name=RX1 TZL



Statistics: (S)

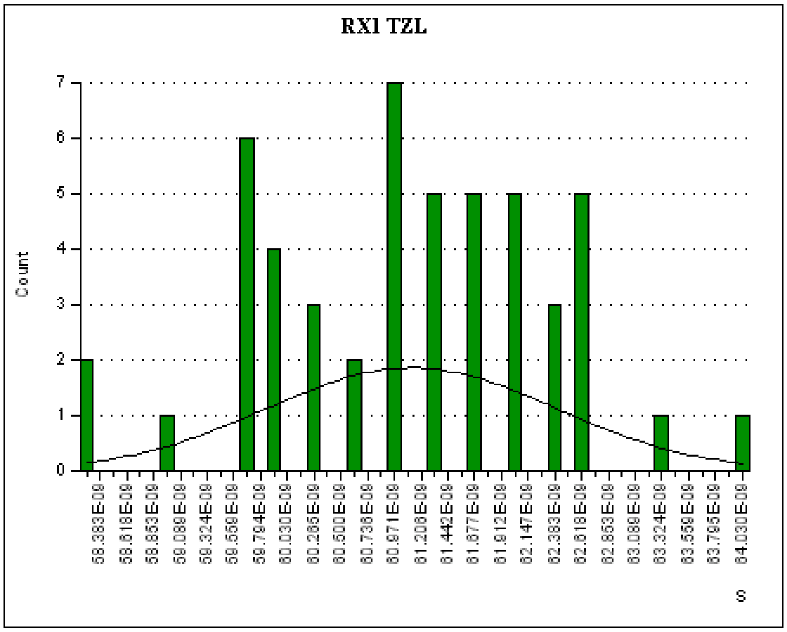
Min	56.095E-09	**Skew**	-0.0225
Max	59.147E-09	**StatHigh**	N/A
Mean	57.633E-09	**StatLow**	N/A
StdDev	928.633E-12	**NWithinSpec**	N/A
25%	56.774E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	60.419E-09	**90%**	58.808E-09
		Range	3.052E-09
Mean-3*StdDev	54.847E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.005, Test.Name=RX1 TZL



Statistics: (S)

Min	58.265E-09	**StatLow**	N/A
Max	64.030E-09	**NWithinSpec**	N/A
Mean	61.093E-09	**NOutsideSpec**	N/A
StdDev	1.261E-09	**90%**	62.673E-09
25%	59.961E-09	**Range**	5.765E-09
Mean+3*StdDev	64.875E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	57.311E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.1579		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

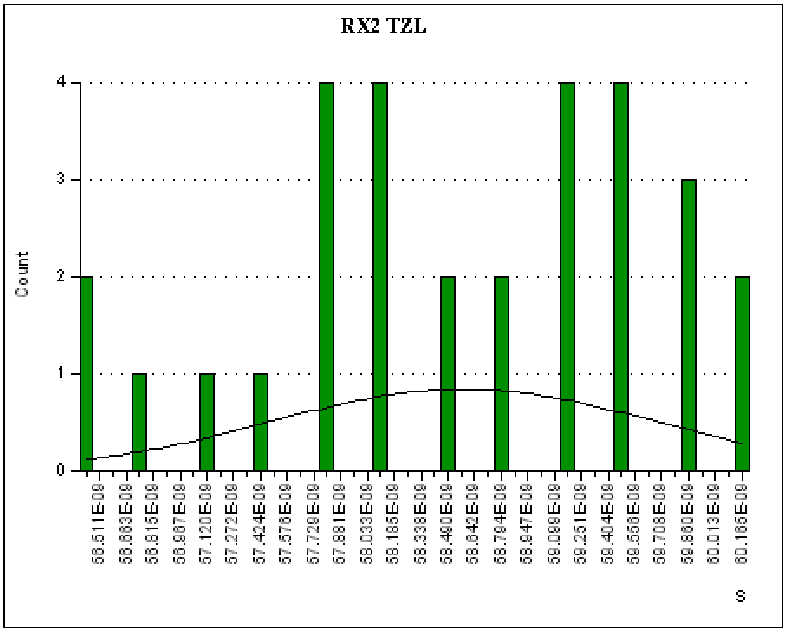
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.006, Test.Name=RX2 TZL



Statistics: (S)

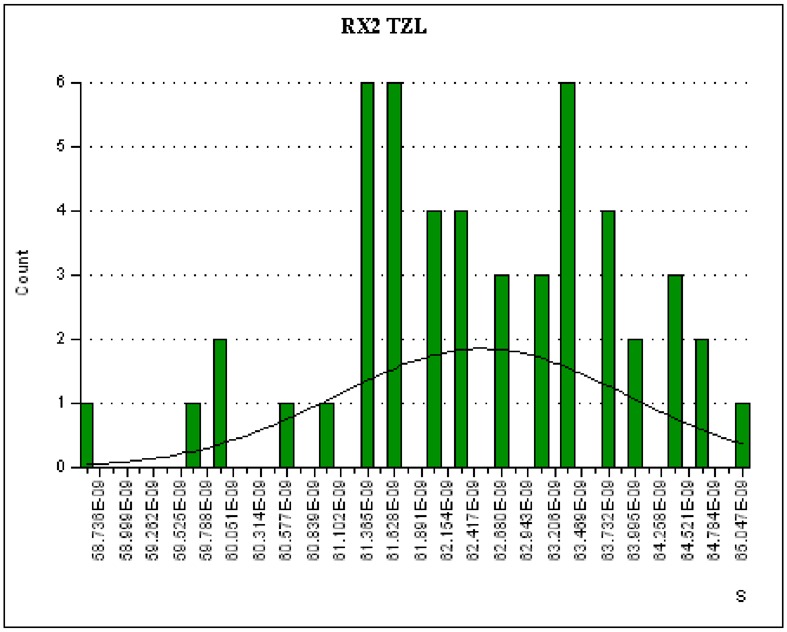
Min	56.435E-09	**Skew**	-0.3866
Max	60.165E-09	**StatHigh**	N/A
Mean	58.560E-09	**StatLow**	N/A
StdDev	1.076E-09	**NWithinSpec**	N/A
25%	57.791E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	61.787E-09	**90%**	59.826E-09
		Range	3.730E-09
Mean-3*StdDev	55.332E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.006, Test.Name=RX2 TZL



Statistics: (S)

Min	58.604E-09	**StatLow**	N/A
Max	65.047E-09	**NWithinSpec**	N/A
Mean	62.450E-09	**NOutsideSpec**	N/A
StdDev	1.415E-09	**90%**	64.369E-09
25%	61.656E-09	**Range**	6.443E-09
Mean+3*StdDev	66.695E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	58.204E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.3696		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

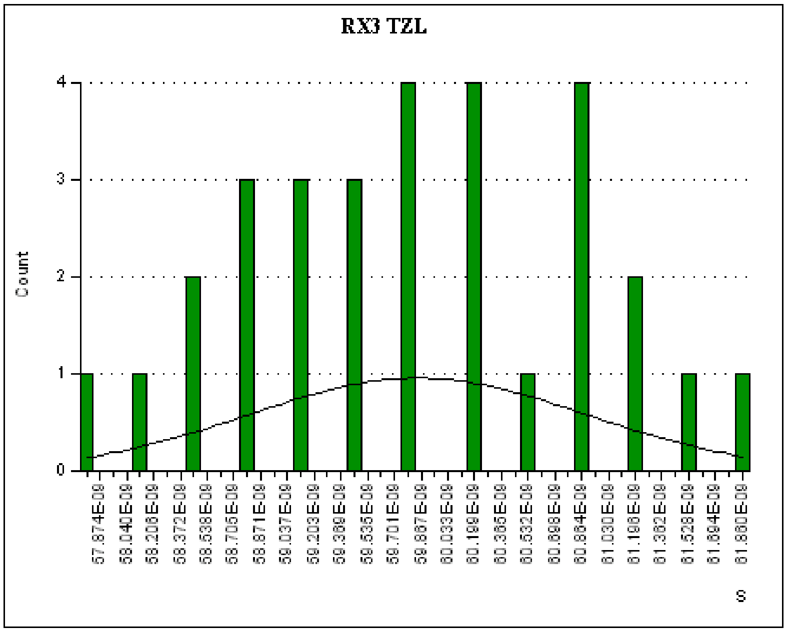
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.007, Test.Name=RX3 TZL



Statistics: (S)

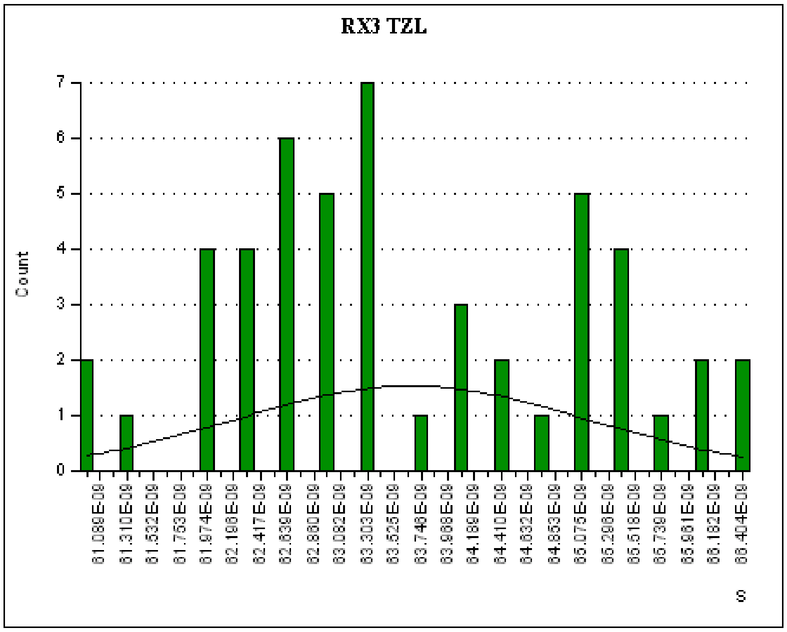
Min	57.791E-09	**Skew**	0.0154
Max	61.860E-09	**StatHigh**	N/A
Mean	59.826E-09	**StatLow**	N/A
StdDev	1.039E-09	**NWithinSpec**	N/A
25%	59.147E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	62.941E-09	**90%**	61.182E-09
		Range	4.069E-09
Mean-3*StdDev	56.710E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.007, Test.Name=RX3 TZL



Statistics: (S)

Min	60.978E-09	**StatLow**	N/A
Max	66.404E-09	**NWithinSpec**	N/A
Mean	63.637E-09	**NOutsideSpec**	N/A
StdDev	1.439E-09	**90%**	65.556E-09
25%	62.673E-09	**Range**	5.426E-09
Mean+3*StdDev	67.954E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	59.319E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.2457		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

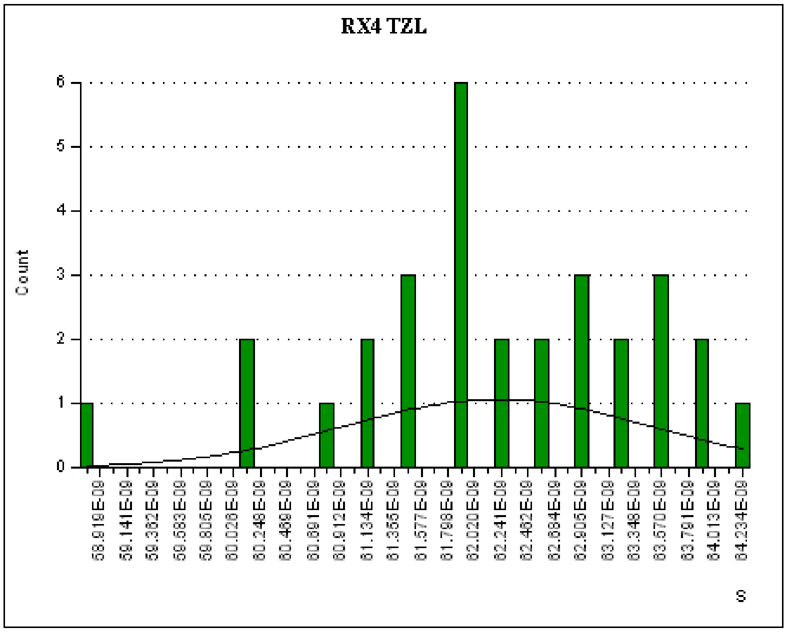
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.008, Test.Name=RX4 TZL



Statistics: (S)

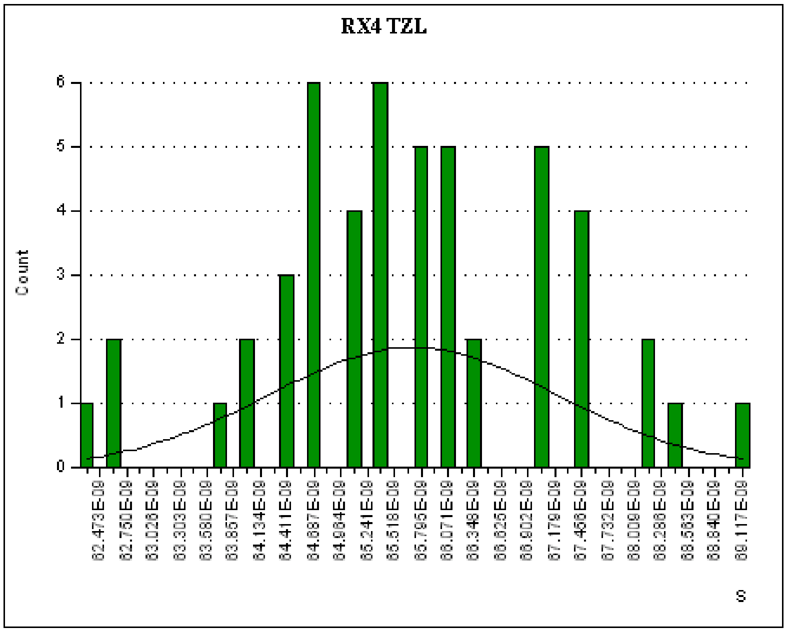
Min	58.808E-09	**Skew**	-0.5726
Max	64.234E-09	**StatHigh**	N/A
Mean	62.177E-09	**StatLow**	N/A
StdDev	1.243E-09	**NWithinSpec**	N/A
25%	61.521E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	65.907E-09	**90%**	63.726E-09
		Range	5.426E-09
Mean-3*StdDev	58.447E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.008, Test.Name=RX4 TZL



Statistics: (S)

Min	62.334E-09	**StatLow**	N/A
Max	69.117E-09	**NWithinSpec**	N/A
Mean	65.678E-09	**NOutsideSpec**	N/A
StdDev	1.474E-09	**90%**	67.421E-09
25%	64.708E-09	**Range**	6.782E-09
Mean+3*StdDev	70.101E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	61.255E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.0290		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

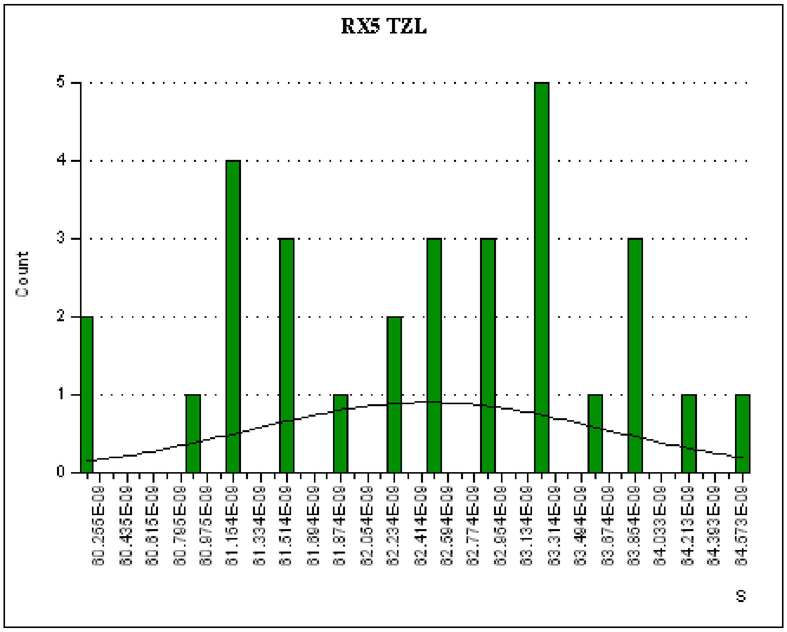
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.009, Test.Name=RX5 TZL



Statistics: (S)

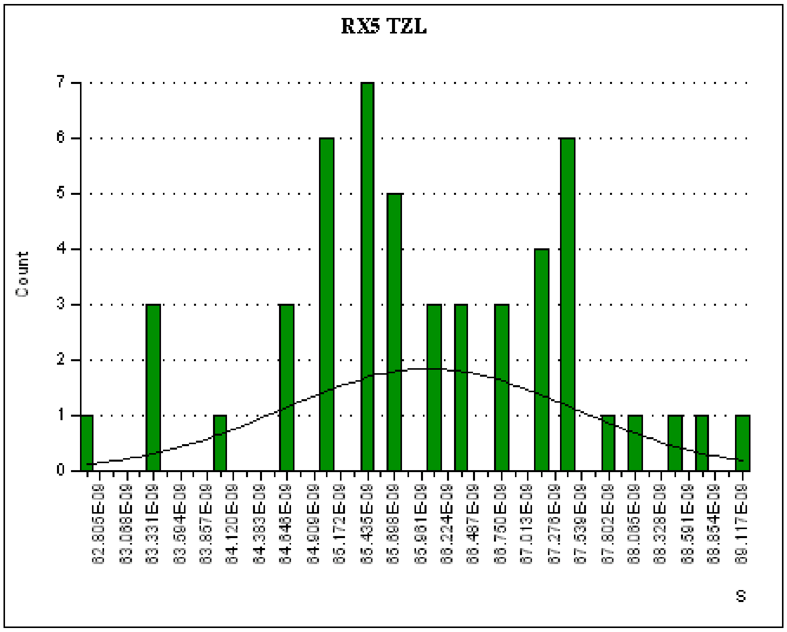
Min	60.165E-09	**Skew**	-0.1971
Max	64.573E-09	**StatHigh**	N/A
Mean	62.437E-09	**StatLow**	N/A
StdDev	1.192E-09	**NWithinSpec**	N/A
25%	61.521E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	66.013E-09	**90%**	63.895E-09
		Range	4.408E-09
Mean-3*StdDev	58.861E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.009, Test.Name=RX5 TZL



Statistics: (S)

Min	62.673E-09	**StatLow**	N/A
Max	69.117E-09	**NWithinSpec**	N/A
Mean	66.004E-09	**NOutsideSpec**	N/A
StdDev	1.423E-09	**90%**	67.591E-09
25%	65.047E-09	**Range**	6.443E-09
Mean+3*StdDev	70.274E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	61.733E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.0737		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

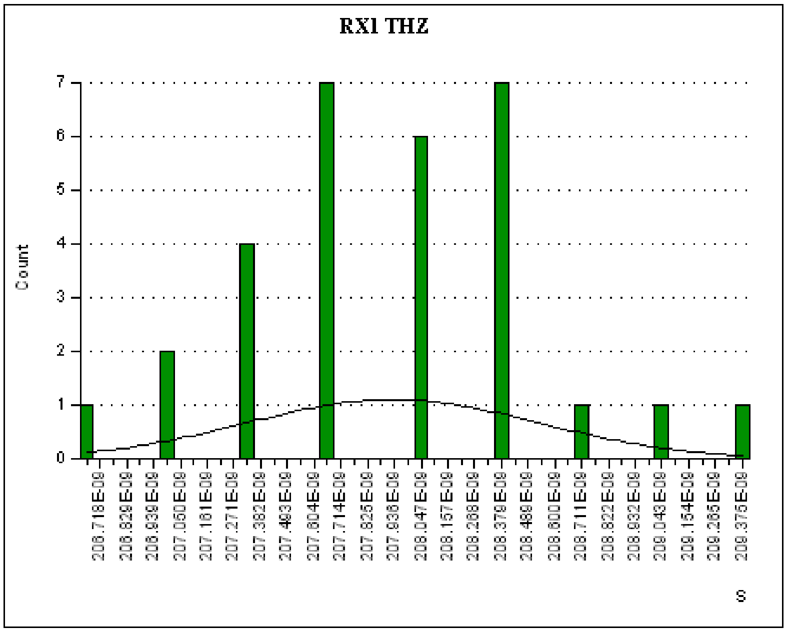
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.010, Test.Name=RX1 THZ



Statistics: (S)

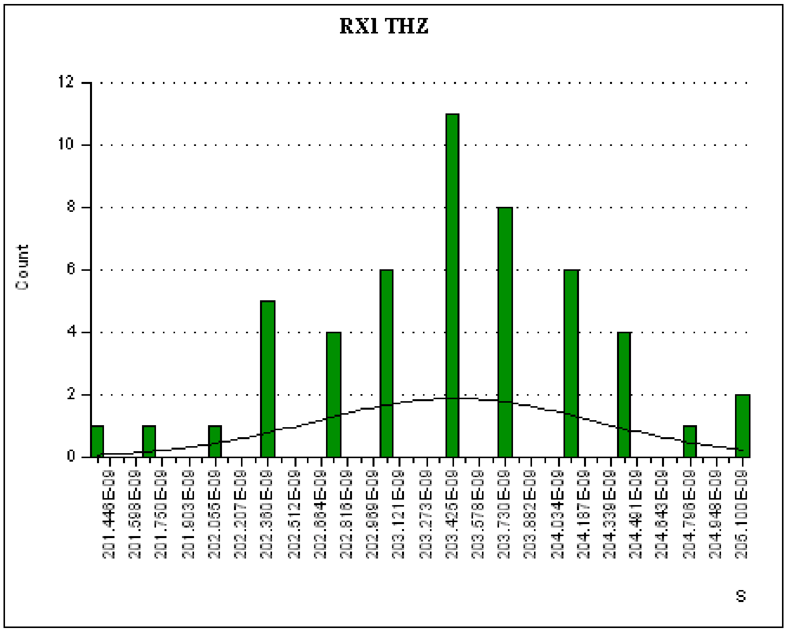
Min	206.662E-09	**Skew**	0.2089
Max	209.375E-09	**StatHigh**	N/A
Mean	207.917E-09	**StatLow**	N/A
StdDev	598.408E-12	**NWithinSpec**	N/A
25%	207.680E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	209.712E-09	**90%**	208.528E-09
		Range	2.713E-09
Mean-3*StdDev	206.122E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.010, Test.Name=RX1 THZ



Statistics: (S)

Min	201.370E-09	**StatLow**	N/A
Max	205.100E-09	**NWithinSpec**	N/A
Mean	203.418E-09	**NOutsideSpec**	N/A
StdDev	807.612E-12	**90%**	204.422E-09
25%	203.065E-09	**Range**	3.730E-09
Mean+3*StdDev	205.841E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	200.995E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.2098		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

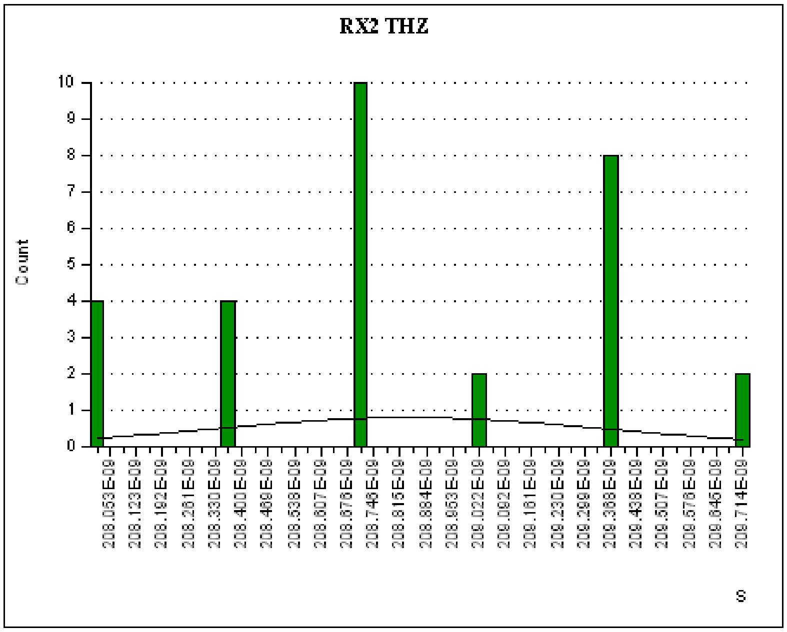
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.011, Test.Name=RX2 THZ



Statistics: (S)

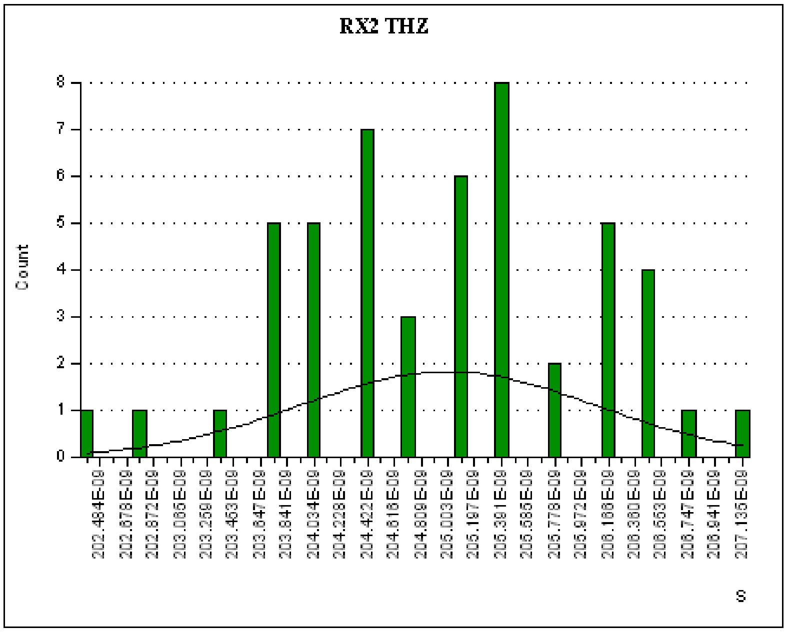
Min	208.019E-09	**Skew**	0.0152
Max	209.714E-09	**StatHigh**	N/A
Mean	208.833E-09	**StatLow**	N/A
StdDev	516.217E-12	**NWithinSpec**	N/A
25%	208.358E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	210.381E-09	**90%**	209.375E-09
		Range	1.696E-09
Mean-3*StdDev	207.284E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.011, Test.Name=RX2 THZ



Statistics: (S)

Min	202.387E-09	**StatLow**	N/A
Max	207.135E-09	**NWithinSpec**	N/A
Mean	204.978E-09	**NOutsideSpec**	N/A
StdDev	1.054E-09	**90%**	206.456E-09
25%	204.083E-09	**Range**	4.748E-09
Mean+3*StdDev	208.141E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	201.815E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.1587		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

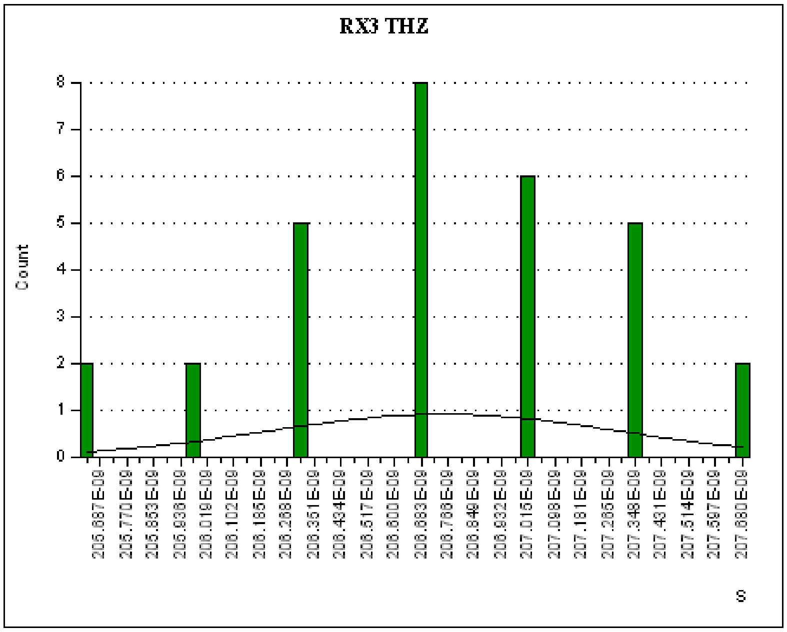
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.012, Test.Name=RX3 THZ



Statistics: (S)

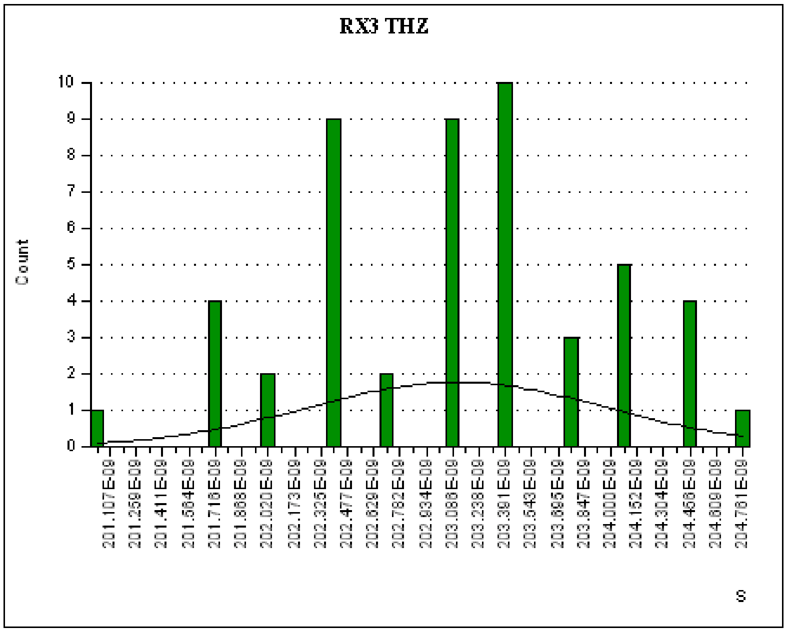
Min	205.645E-09	**Skew**	-0.2455
Max	207.680E-09	**StatHigh**	N/A
Mean	206.742E-09	**StatLow**	N/A
StdDev	539.380E-12	**NWithinSpec**	N/A
25%	206.323E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	208.360E-09	**90%**	207.341E-09
		Range	2.035E-09
Mean-3*StdDev	205.123E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.012, Test.Name=RX3 THZ



Statistics: (S)

Min	201.031E-09	**StatLow**	N/A
Max	204.761E-09	**NWithinSpec**	N/A
Mean	203.093E-09	**NOutsideSpec**	N/A
StdDev	855.254E-12	**90%**	204.252E-09
25%	202.387E-09	**Range**	3.730E-09
Mean+3*StdDev	205.658E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	200.527E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.1654		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

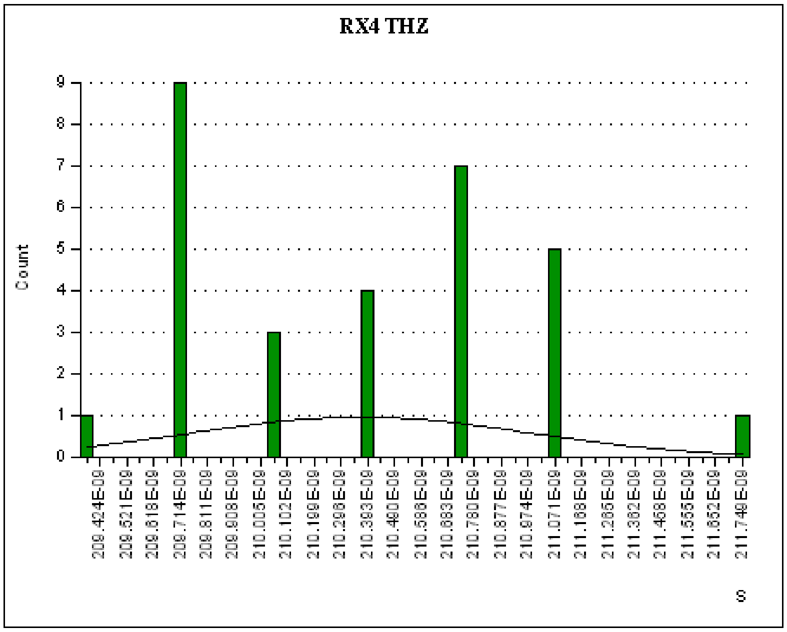
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.013, Test.Name=RX4 THZ



Statistics: (S)

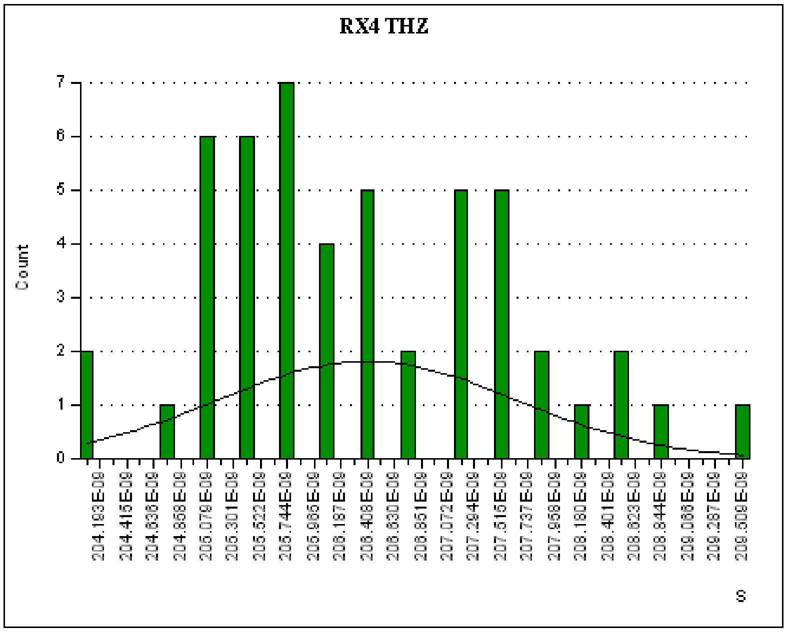
Min	209.375E-09	**Skew**	0.2421
Max	211.749E-09	**StatHigh**	N/A
Mean	210.359E-09	**StatLow**	N/A
StdDev	599.720E-12	**NWithinSpec**	N/A
25%	209.714E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	212.158E-09	**90%**	211.071E-09
		Range	2.374E-09
Mean-3*StdDev	208.560E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.013, Test.Name=RX4 THZ



Statistics: (S)

Min	204.083E-09	**StatLow**	N/A
Max	209.509E-09	**NWithinSpec**	N/A
Mean	206.382E-09	**NOutsideSpec**	N/A
StdDev	1.215E-09	**90%**	207.983E-09
25%	205.439E-09	**Range**	5.426E-09
Mean+3*StdDev	210.026E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	202.738E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.4314		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

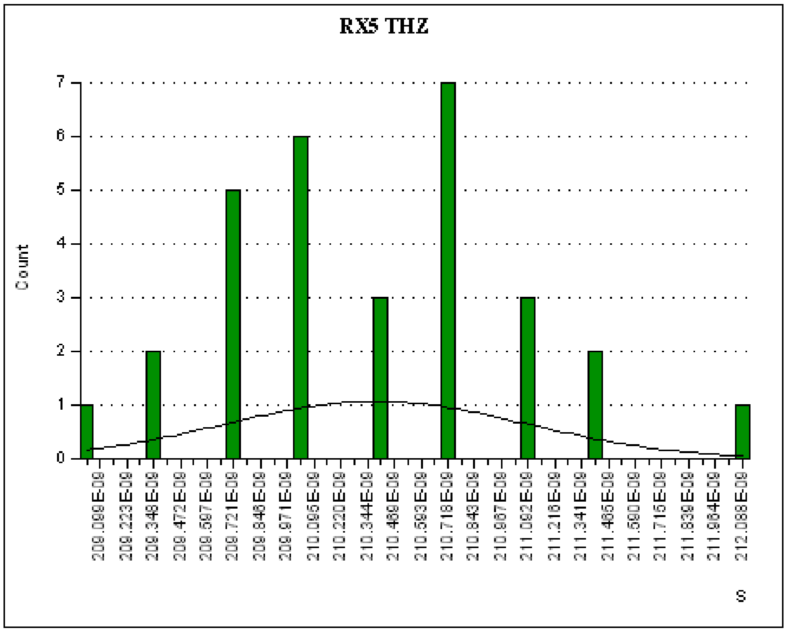
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.014, Test.Name=RX5 THZ



Statistics: (S)

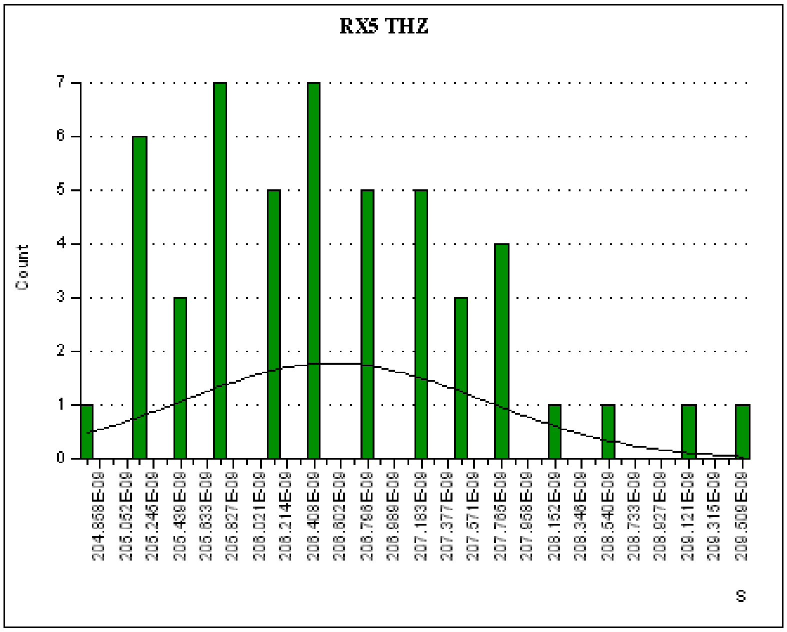
Min	209.036E-09	**Skew**	0.3019
Max	212.088E-09	**StatHigh**	N/A
Mean	210.370E-09	**StatLow**	N/A
StdDev	695.166E-12	**NWithinSpec**	N/A
25%	209.714E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	212.456E-09	**90%**	211.240E-09
		Range	3.052E-09
Mean-3*StdDev	208.285E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.014, Test.Name=RX5 THZ



Statistics: (S)

Min	204.761E-09	**StatLow**	N/A
Max	209.509E-09	**NWithinSpec**	N/A
Mean	206.531E-09	**NOutsideSpec**	N/A
StdDev	1.084E-09	**90%**	207.813E-09
25%	205.778E-09	**Range**	4.748E-09
Mean+3*StdDev	209.783E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	203.279E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	0.6394		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

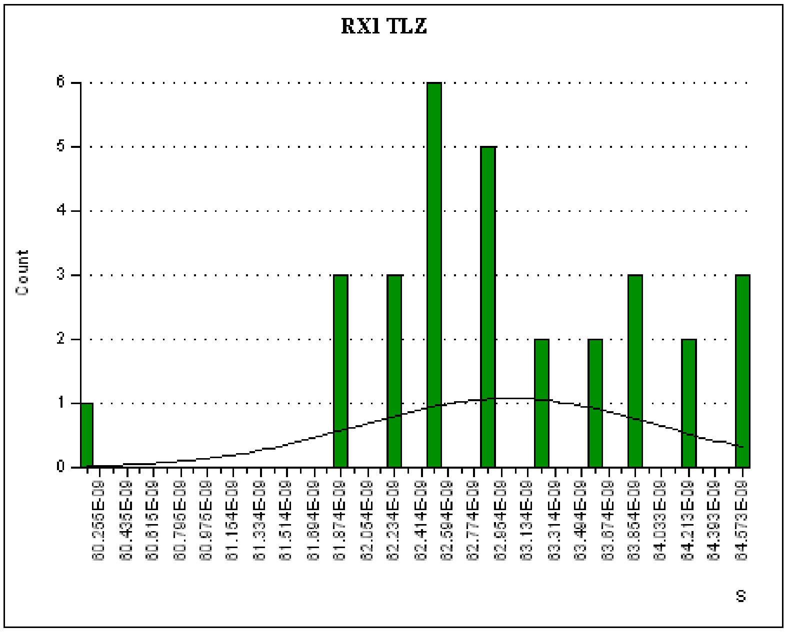
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.015, Test.Name=RX1 TLZ



Statistics: (S)

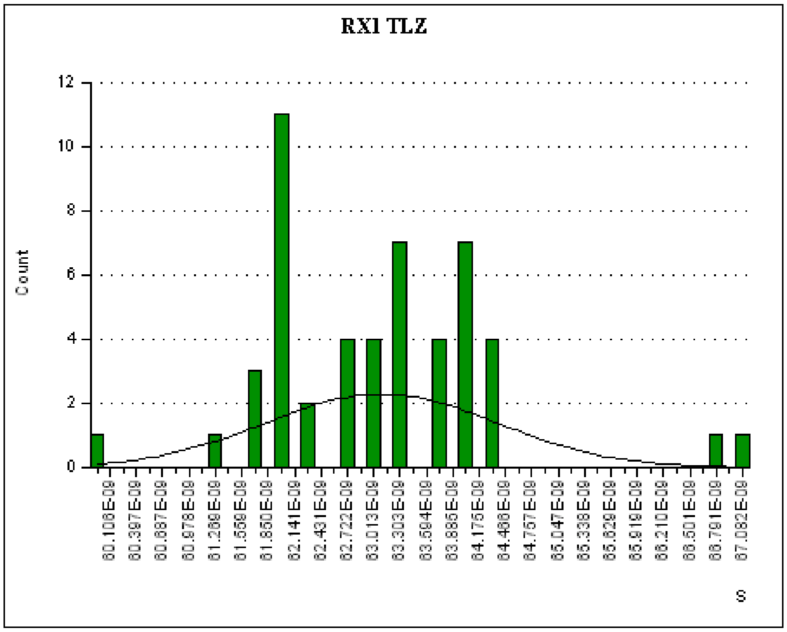
Min	60.165E-09	**Skew**	-0.3600
Max	64.573E-09	**StatHigh**	N/A
Mean	62.979E-09	**StatLow**	N/A
StdDev	996.269E-12	**NWithinSpec**	N/A
25%	62.539E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	65.968E-09	**90%**	64.404E-09
		Range	4.408E-09
Mean-3*StdDev	59.991E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.015, Test.Name=RX1 TLZ



Statistics: (S)

Min	59.961E-09	**StatLow**	N/A
Max	67.082E-09	**NWithinSpec**	N/A
Mean	63.067E-09	**NOutsideSpec**	N/A
StdDev	1.262E-09	**90%**	64.369E-09
25%	61.995E-09	**Range**	7.121E-09
Mean+3*StdDev	66.853E-09	**NOutsideSpec**	N/A
Mean-3*StdDev	59.281E-09	**Cp**	N/A
Cpk	N/A	**Cpl**	N/A
Skew	0.7645	**Cpu**	N/A
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

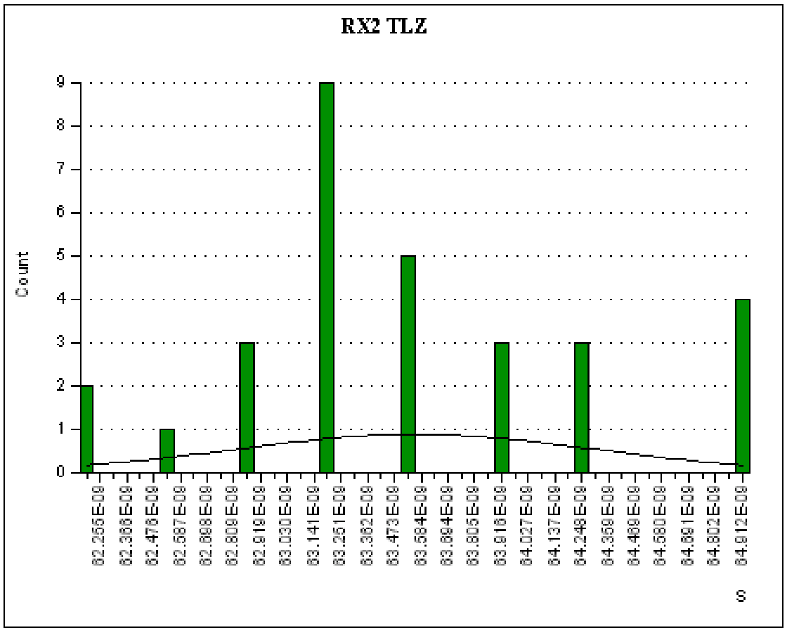
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.016, Test.Name=RX2 TLZ



Statistics: (S)

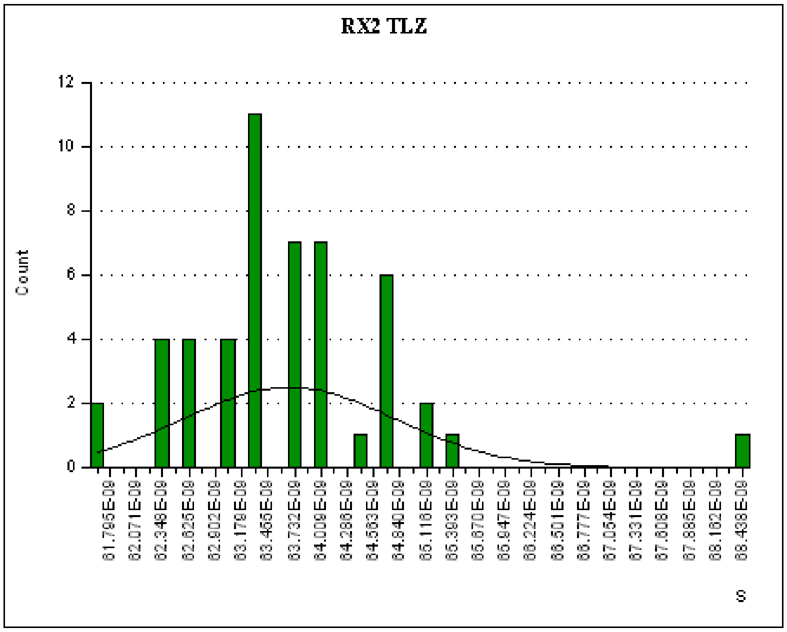
Min	62.199E-09	**Skew**	0.3761
Max	64.912E-09	**StatHigh**	N/A
Mean	63.545E-09	**StatLow**	N/A
StdDev	747.662E-12	**NWithinSpec**	N/A
25%	63.217E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	65.788E-09	**90%**	64.912E-09
		Range	2.713E-09
Mean-3*StdDev	61.302E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.016, Test.Name=RX2 TLZ



Statistics: (S)

Min	61.656E-09	**StatLow**	N/A
Max	68.438E-09	**NWithinSpec**	N/A
Mean	63.657E-09	**NOutsideSpec**	N/A
StdDev	1.101E-09	**90%**	64.708E-09
25%	63.013E-09	**Range**	6.782E-09
Mean+3*StdDev	66.960E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	60.354E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	1.5468		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

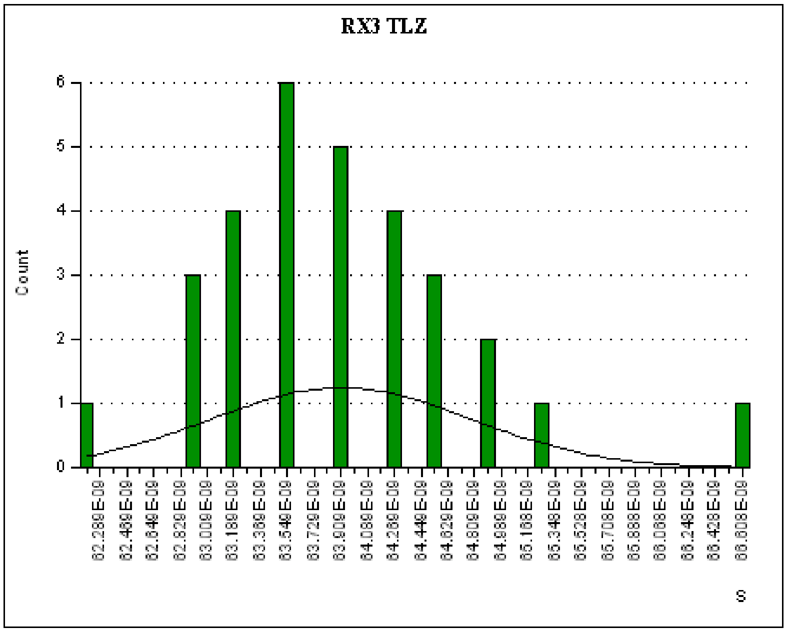
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.017, Test.Name=RX3 TLZ



Statistics: (S)

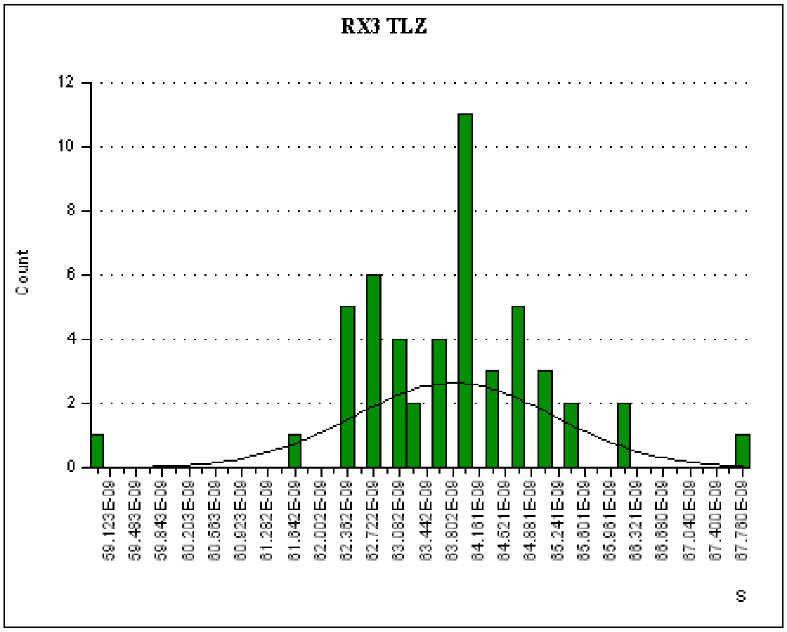
Min	62.199E-09	**Skew**	0.9267
Max	66.608E-09	**StatHigh**	N/A
Mean	63.895E-09	**StatLow**	N/A
StdDev	863.431E-12	**NWithinSpec**	N/A
25%	63.217E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	66.485E-09	**90%**	64.912E-09
		Range	4.408E-09
Mean-3*StdDev	61.305E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.017, Test.Name=RX3 TLZ



Statistics: (S)

Min	58.943E-09	**StatLow**	N/A
Max	67.760E-09	**NWithinSpec**	N/A
Mean	63.772E-09	**NOutsideSpec**	N/A
StdDev	1.361E-09	**90%**	65.217E-09
25%	62.673E-09	**Range**	8.817E-09
Mean+3*StdDev	67.855E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	59.690E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-0.3351		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

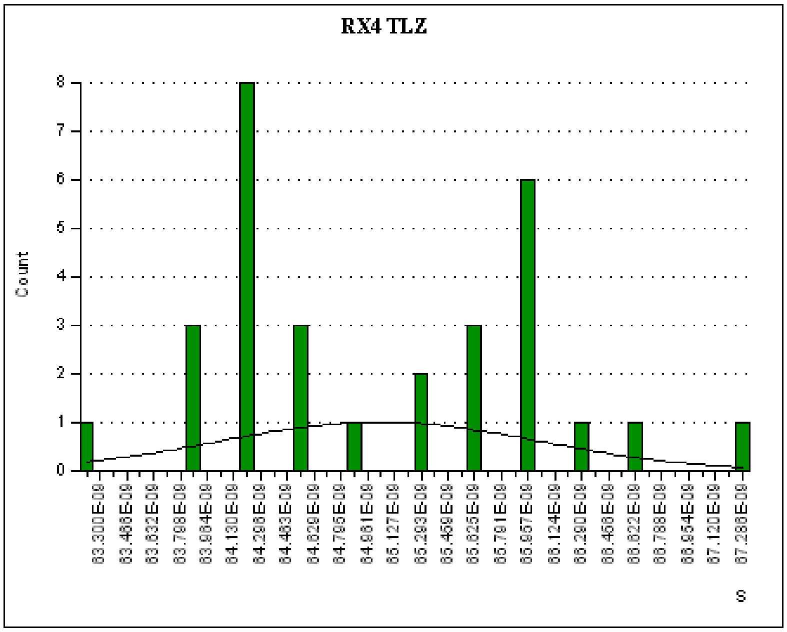
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.018, Test.Name=RX4 TLZ



Statistics: (S)

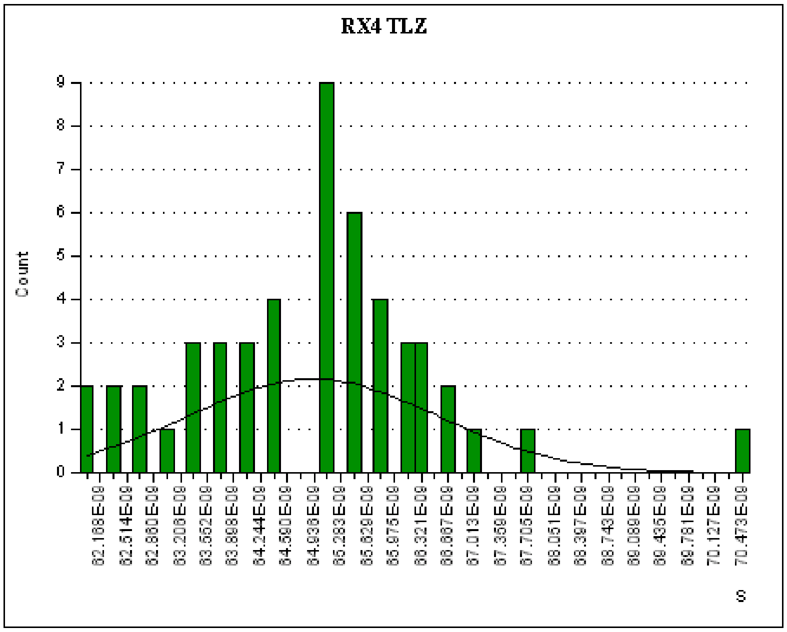
Min	63.217E-09	**Skew**	0.3490
Max	67.286E-09	**StatHigh**	N/A
Mean	65.014E-09	**StatLow**	N/A
StdDev	980.224E-12	**NWithinSpec**	N/A
25%	64.234E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	67.955E-09	**90%**	66.099E-09
		Range	4.069E-09
Mean-3*StdDev	62.073E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.018, Test.Name=RX4 TLZ



Statistics: (S)

Min	61.995E-09	**StatLow**	N/A
Max	70.473E-09	**NWithinSpec**	N/A
Mean	64.891E-09	**NOutsideSpec**	N/A
StdDev	1.594E-09	**90%**	66.573E-09
25%	63.691E-09	**Range**	8.478E-09
Mean+3*StdDev	69.673E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	60.110E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.5773		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

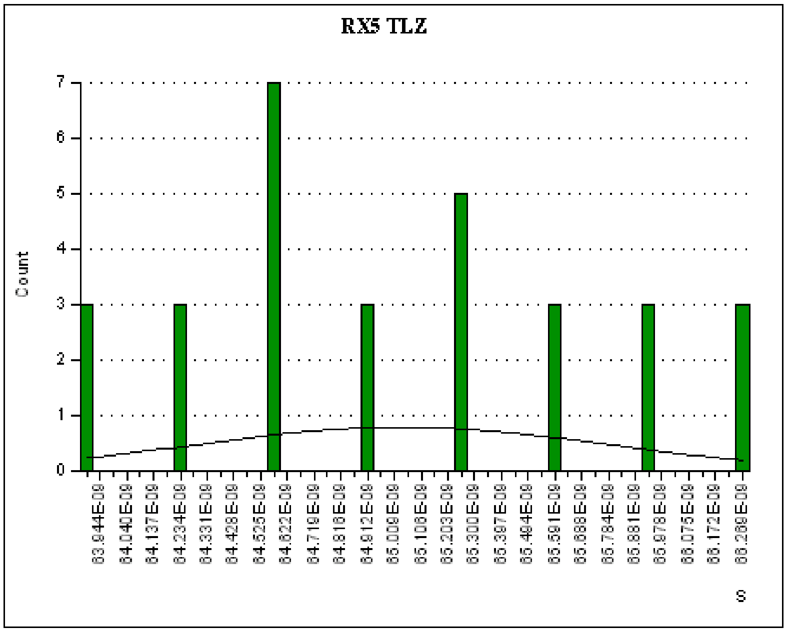
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=19.019, Test.Name=RX5 TLZ



Statistics: (S)

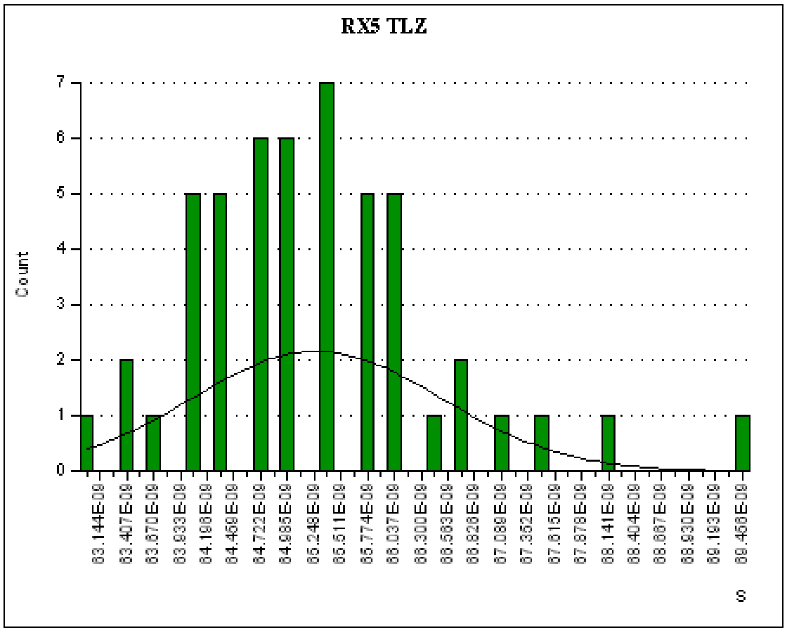
Min	63.895E-09	**Skew**	0.2002
Max	66.269E-09	**StatHigh**	N/A
Mean	65.025E-09	**StatLow**	N/A
StdDev	730.767E-12	**NWithinSpec**	N/A
25%	64.573E-09	**NOutsideSpec**	N/A
Mean+3*StdDev	67.218E-09	**90%**	66.099E-09
		Range	2.374E-09
Mean-3*StdDev	62.833E-09	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=19.019, Test.Name=RX5 TLZ



Statistics: (S)

Min	63.013E-09	**StatLow**	N/A
Max	69.456E-09	**NWithinSpec**	N/A
Mean	65.251E-09	**NOutsideSpec**	N/A
StdDev	1.214E-09	**90%**	66.743E-09
25%	64.369E-09	**Range**	6.443E-09
Mean+3*StdDev	68.893E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	61.609E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.9863		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

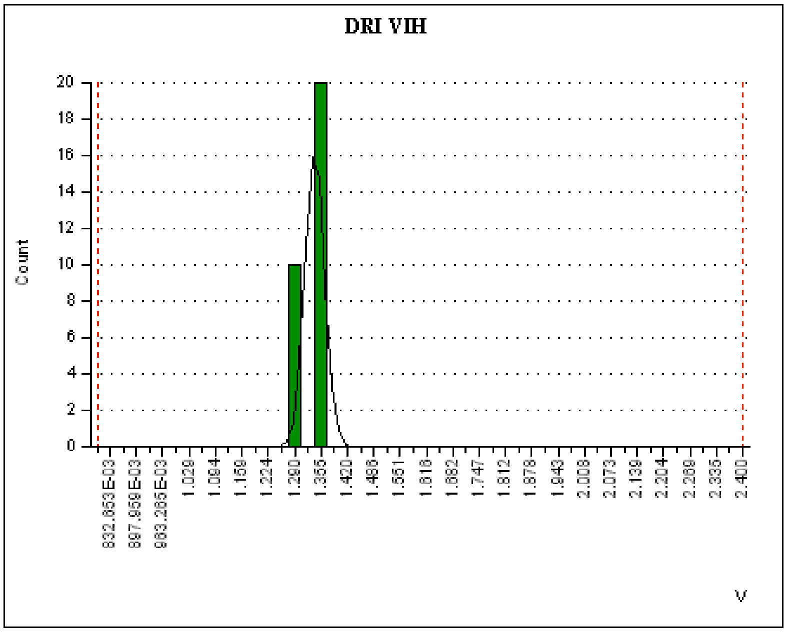
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=20.000, Test.Name=DRI VIH



Statistics: (V)

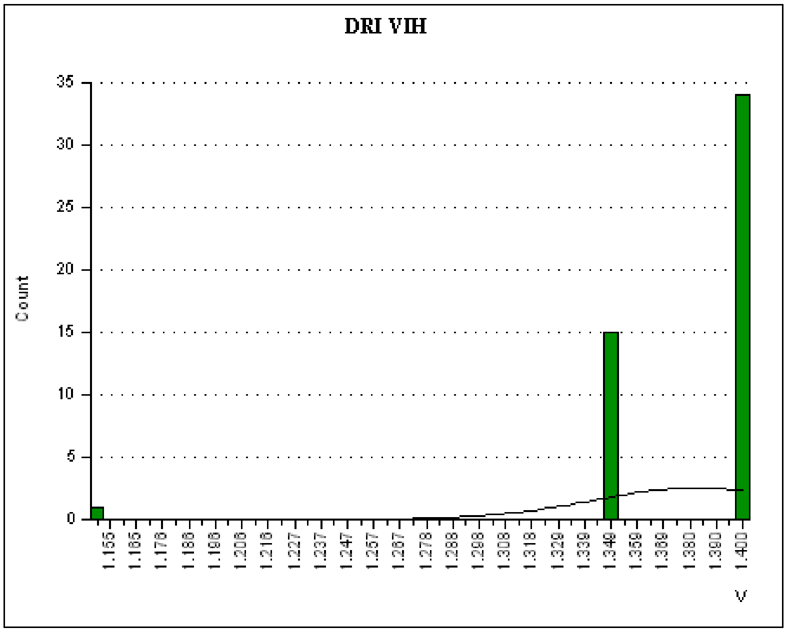
Min	1.300	**Skew**	-0.7449
Max	1.350	**StatHigh**	N/A
Mean	1.333	**StatLow**	N/A
StdDev	23.973E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.405	**90%**	1.350
		Range	50.000E-03
Mean-3*StdDev	1.261	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.000, Test.Name=DRI VIH



Statistics: (V)

Min	1.150	**StatLow**	N/A
Max	1.400	**NWithinSpec**	N/A
Mean	1.380	**NOutsideSpec**	N/A
StdDev	40.406E-03	**90%**	1.400
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.501	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	1.259	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	-3.9637		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

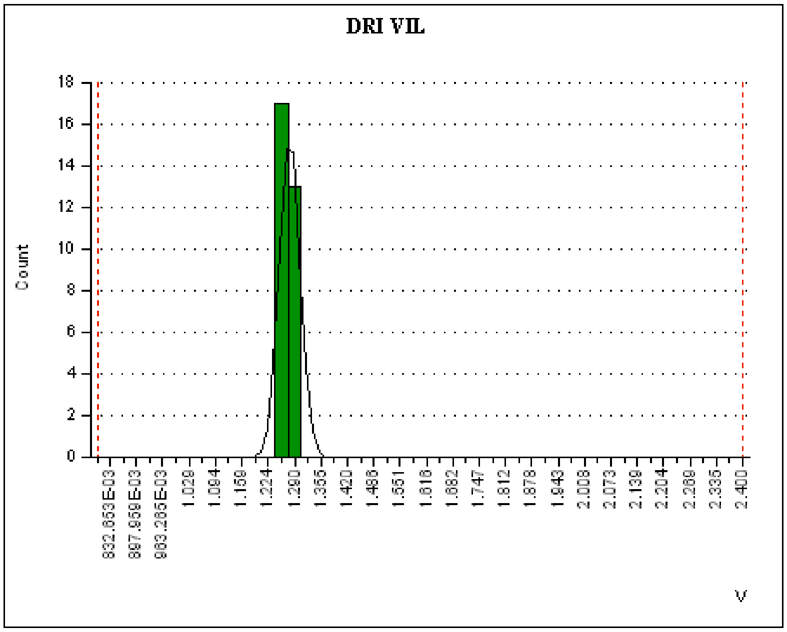
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=20.001, Test.Name=DRI VIL



Statistics: (V)

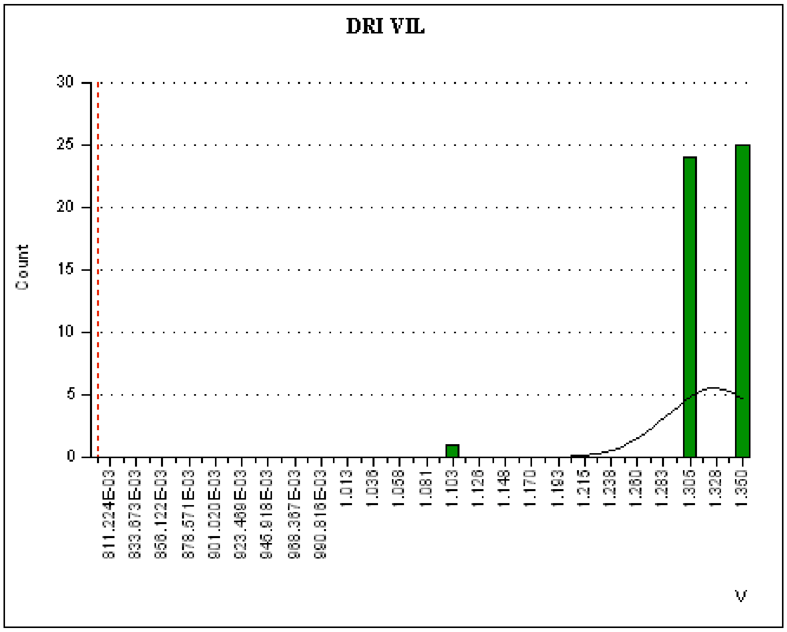
Min	1.250	**Skew**	0.2834
Max	1.300	**StatHigh**	N/A
Mean	1.272	**StatLow**	N/A
StdDev	25.200E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.347	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.196	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.001, Test.Name=DRI VIL



Statistics: (V)

Min	1.100	**StatLow**	N/A
Max	1.350	**NWithinSpec**	50
Mean	1.321	**NOutsideSpec**	0
StdDev	40.520E-03	**90%**	1.350
25%	1.300	**Range**	250.000E-03
Mean+3*StdDev	1.443	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.199	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-3.3253		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

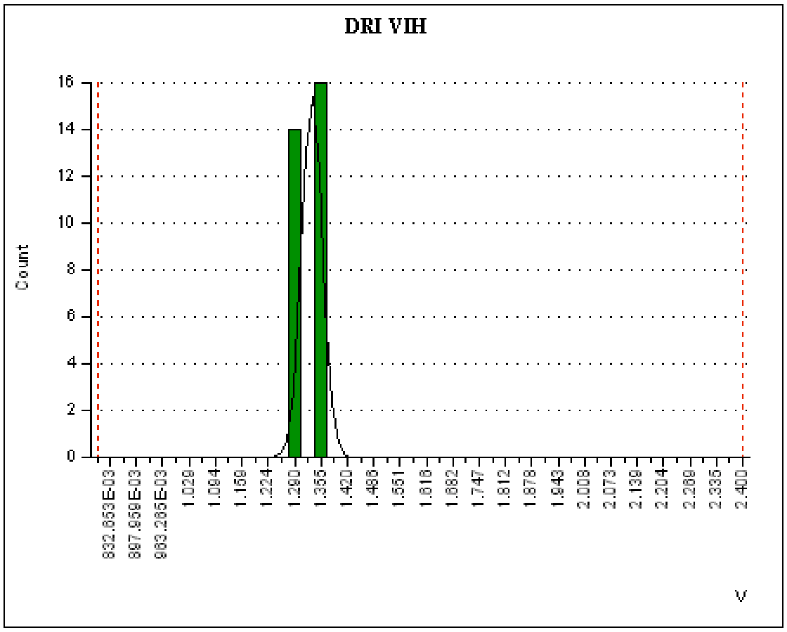
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=20.002, Test.Name=DRI VIH



Statistics: (V)

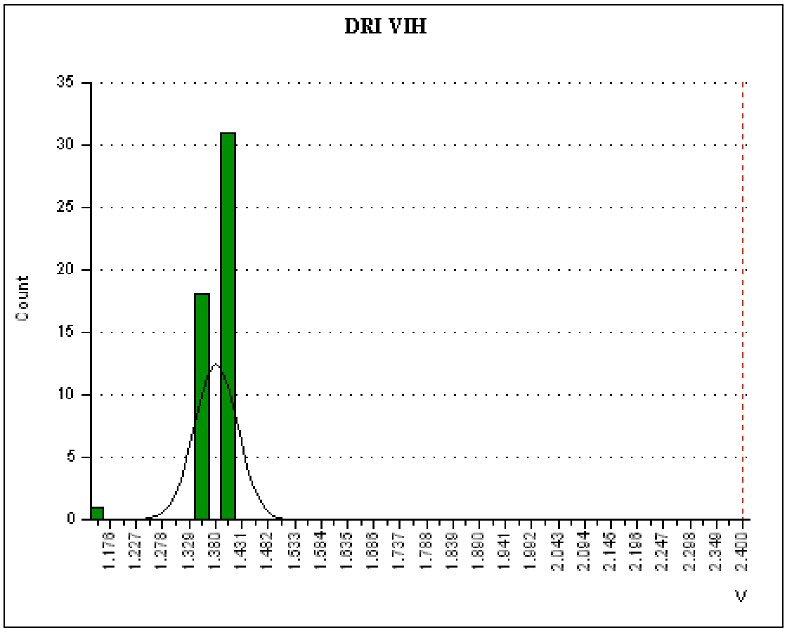
Min	1.300	**Skew**	-0.1408
Max	1.350	**StatHigh**	N/A
Mean	1.327	**StatLow**	N/A
StdDev	25.371E-03	**NWithinSpec**	30
25%	1.300	**NOutsideSpec**	0
Mean+3*StdDev	1.403	**90%**	1.350
		Range	50.000E-03
Mean-3*StdDev	1.251	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.002, Test.Name=DRI VIH



Statistics: (V)

Min	1.150	**StatLow**	N/A
Max	1.400	**NWithinSpec**	50
Mean	1.377	**NOutsideSpec**	0
StdDev	40.670E-03	**90%**	1.400
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.499	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.255	**Cpl**	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-3.6892		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

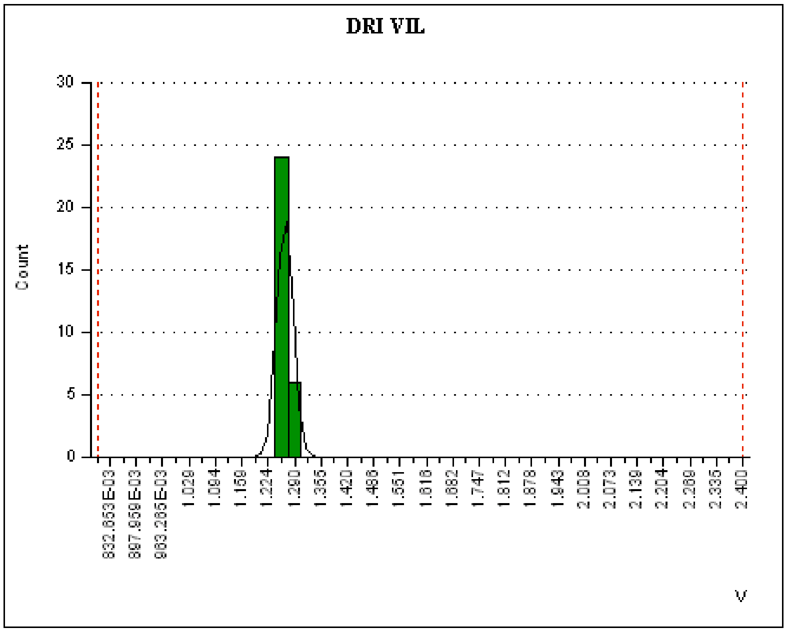
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=20.003, Test.Name=DRI VIL



Statistics: (V)

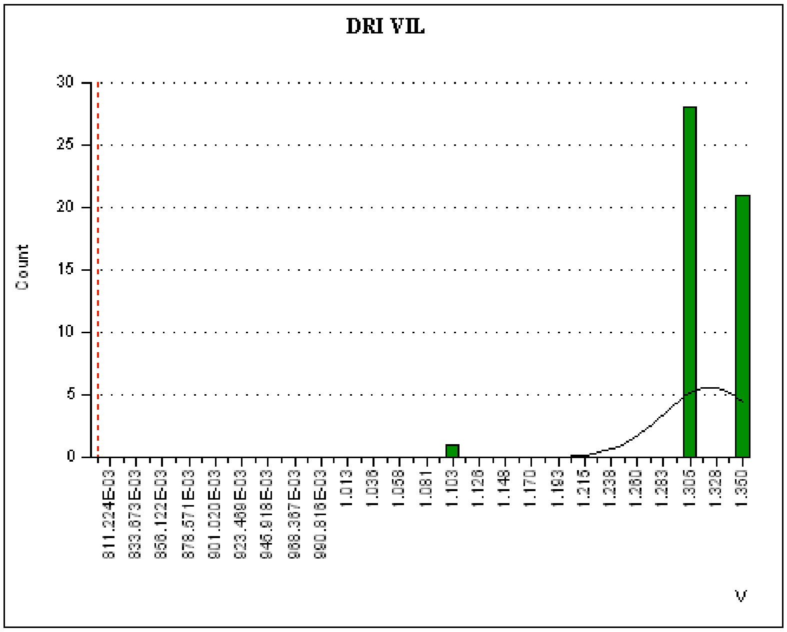
Min	1.250	**Skew**	1.5801
Max	1.300	**StatHigh**	N/A
Mean	1.260	**StatLow**	N/A
StdDev	20.342E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.321	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.199	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.003, Test.Name=DRI VIL



Statistics: (V)

Min	1.100	**StatLow**	N/A
Max	1.350	**NWithinSpec**	50
Mean	1.317	**NOutsideSpec**	0
StdDev	39.911E-03	**90%**	1.350
25%	1.300	**Range**	250.000E-03
Mean+3*StdDev	1.437	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.197	**Cpl**	>4.0000
		Cpu	N/A
Cpk	>4.0000		
Skew	-3.2106		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

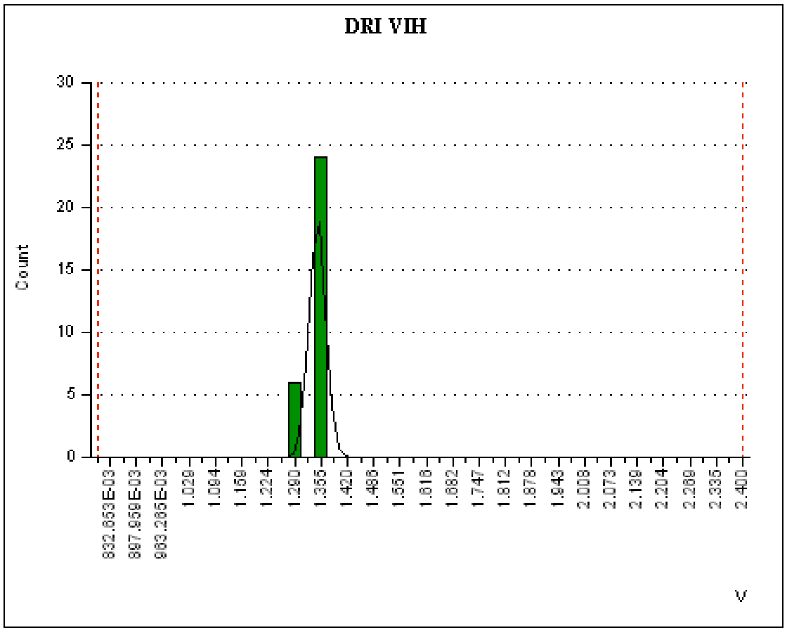
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=20.004, Test.Name=DRI VIH



Statistics: (V)

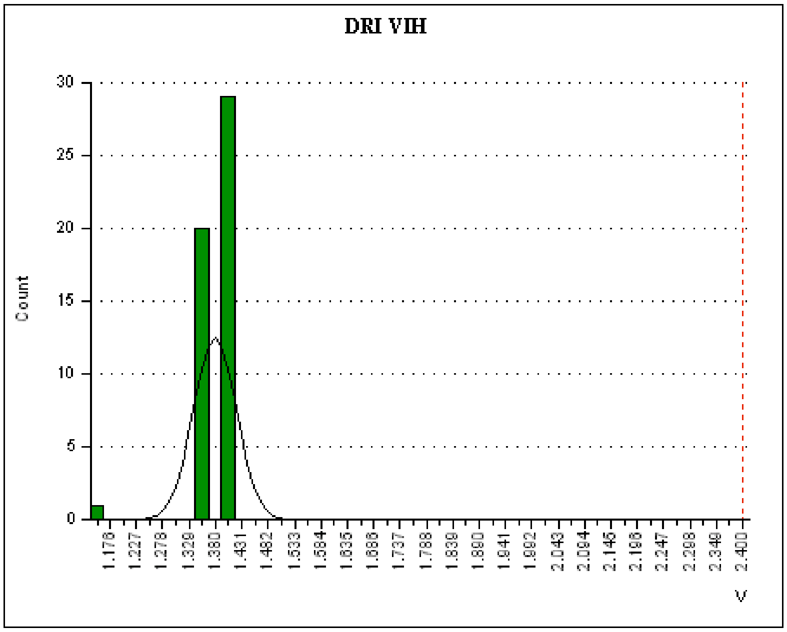
Min	1.300	**Skew**	-1.5801
Max	1.350	**StatHigh**	N/A
Mean	1.340	**StatLow**	N/A
StdDev	20.342E-03	**NWithinSpec**	30
25%	1.350	**NOutsideSpec**	0
Mean+3*StdDev	1.401	**90%**	1.350
		Range	50.000E-03
Mean-3*StdDev	1.279	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.004, Test.Name=DRI VIH



Statistics: (V)

Min	1.150	**StatLow**	N/A
Max	1.400	**NWithinSpec**	50
Mean	1.375	**NOutsideSpec**	0
StdDev	40.720E-03	**90%**	1.400
25%	1.350	**Range**	250.000E-03
Mean+3*StdDev	1.497	**NOutsideSpec**	0
Mean-3*StdDev	1.253	**Cp**	N/A
		Cpl	N/A
Cpk	>4.0000	**Cpu**	>4.0000
Skew	-3.5420		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

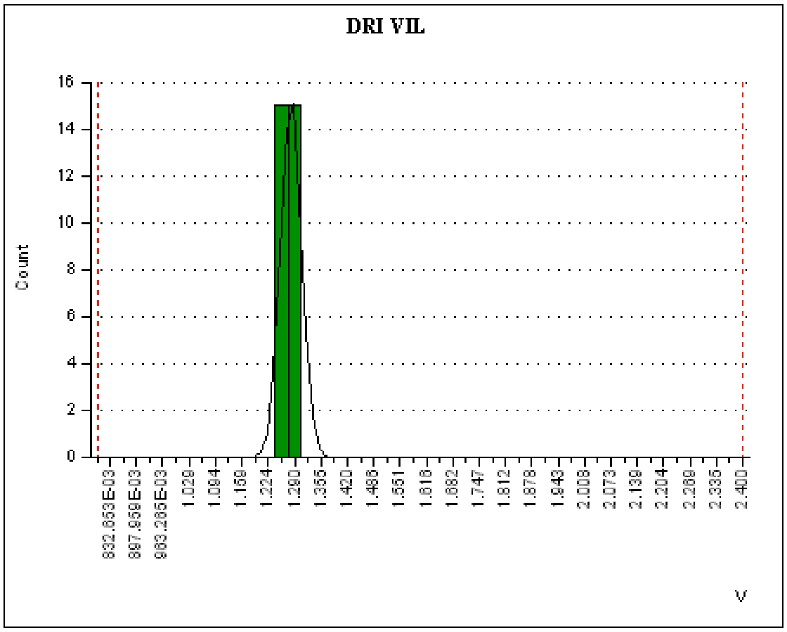
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=20.005, Test.Name=DRI VIL



Statistics: (V)

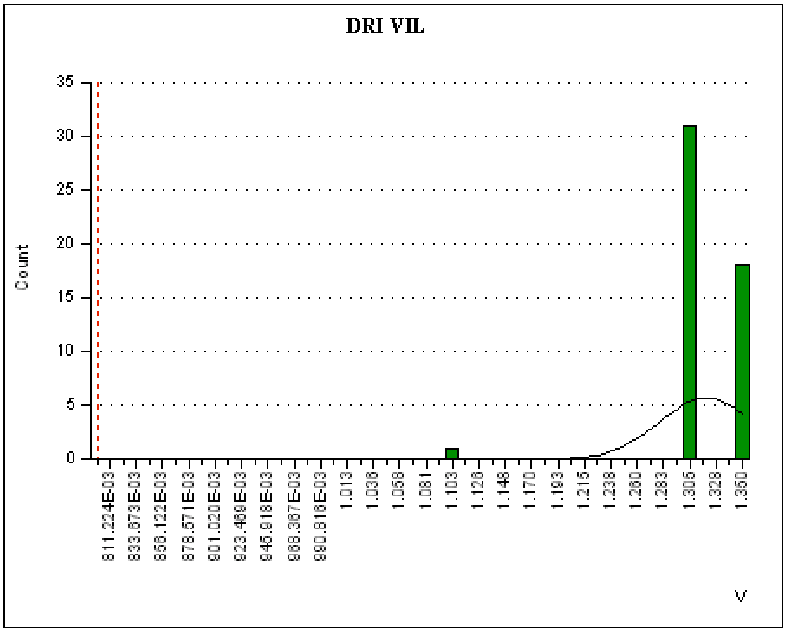
Min	1.250	**Skew**	-0.0000
Max	1.300	**StatHigh**	N/A
Mean	1.275	**StatLow**	N/A
StdDev	25.427E-03	**NWithinSpec**	30
25%	1.250	**NOutsideSpec**	0
Mean+3*StdDev	1.351	**90%**	1.300
		Range	50.000E-03
Mean-3*StdDev	1.199	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=20.005, Test.Name=DRI VIL



Statistics: (V)

Min	1.100	**StatLow**	N/A
Max	1.350	**NWithinSpec**	50
Mean	1.314	**NOutsideSpec**	0
StdDev	39.175E-03	**90%**	1.350
25%	1.300	**Range**	250.000E-03
Mean+3*StdDev	1.432	**NOutsideSpec**	0
		Cp	N/A
Mean-3*StdDev	1.196	**Cpl**	>4.0000
Cpk	>4.0000	**Cpu**	N/A
Skew	-3.1984		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

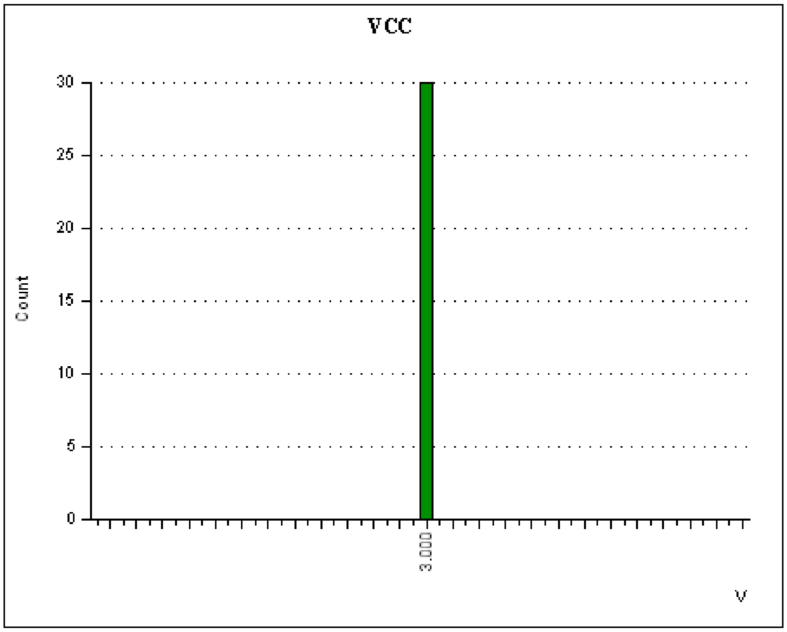
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=21.000, Test.Name=VCC



Statistics: (V)

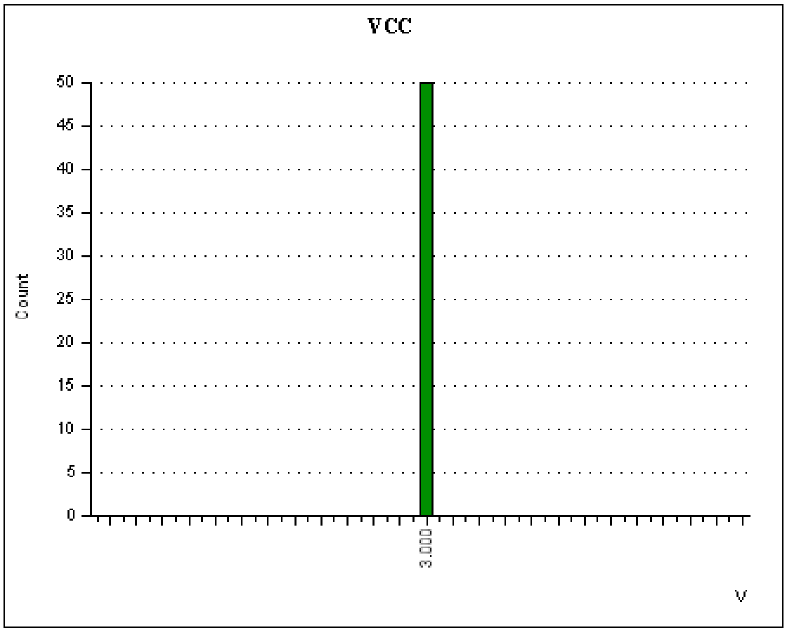
Min	3.000	**Skew**	N/A
Max	3.000	**StatHigh**	N/A
Mean	3.000	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	3.000	**NOutsideSpec**	N/A
Mean+3*StdDev	3.000	**90%**	3.000
		Range	0
Mean-3*StdDev	3.000	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=21.000, Test.Name=VCC



Statistics: (V)

Min	3.000	**StatLow**	N/A
Max	3.000	**NWithinSpec**	N/A
Mean	3.000	**NOutsideSpec**	N/A
StdDev	0	**90%**	3.000
25%	3.000	**Range**	0
Mean+3*StdDev	3.000	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	3.000	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	N/A		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

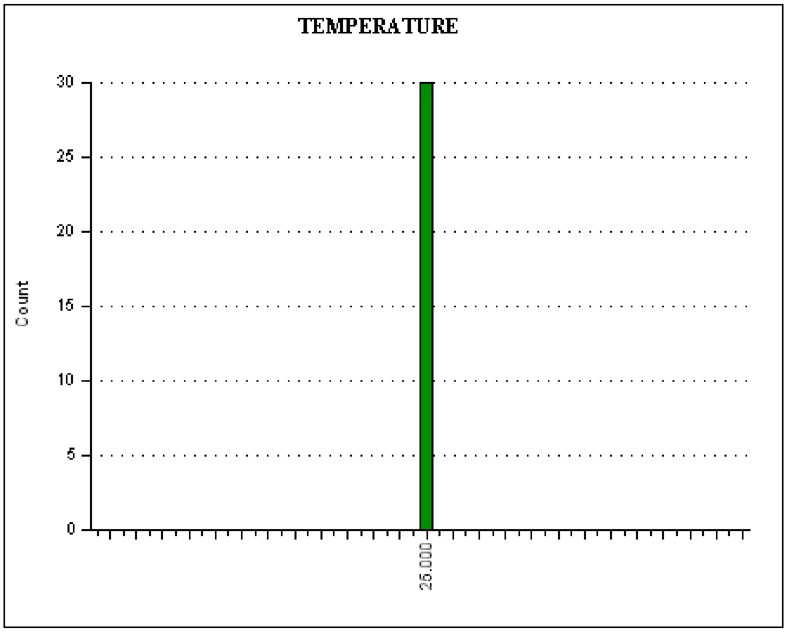
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=21.001, Test.Name=TEMPERATURE



Statistics

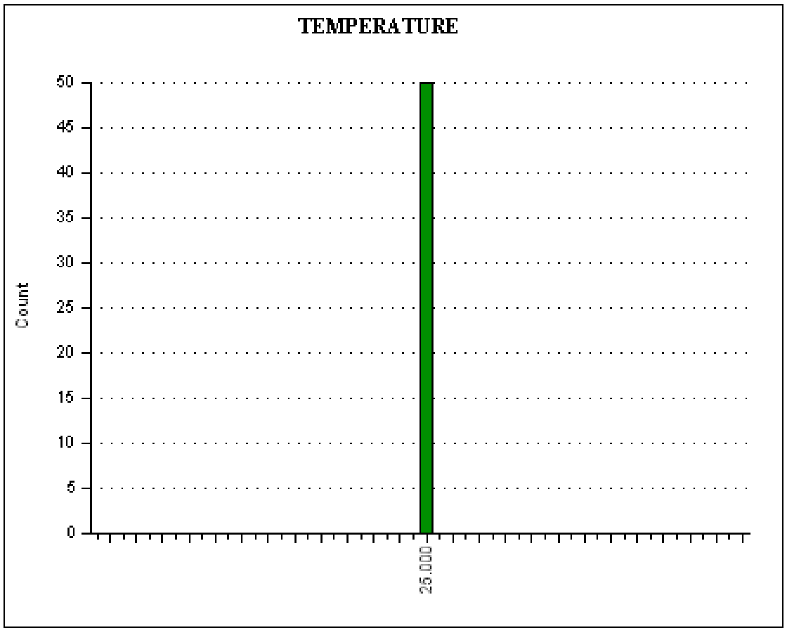
Min	25.000	**Skew**	N/A
Max	25.000	**StatHigh**	N/A
Mean	25.000	**StatLow**	N/A
StdDev	0	**NWithinSpec**	N/A
25%	25.000	**NOutsideSpec**	N/A
Mean+3*StdDev	25.000	**90%**	25.000
		Range	0
Mean-3*StdDev	25.000	**NOutsideSpec**	N/A
Cpk	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=21.001, Test.Name=TEMPERATURE



Statistics

Min	25.000	**StatLow**	N/A
Max	25.000	**NWithinSpec**	N/A
Mean	25.000	**NOutsideSpec**	N/A
StdDev	0	**90%**	25.000
25%	25.000	**Range**	0
Mean+3*StdDev	25.000	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	25.000	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	N/A		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

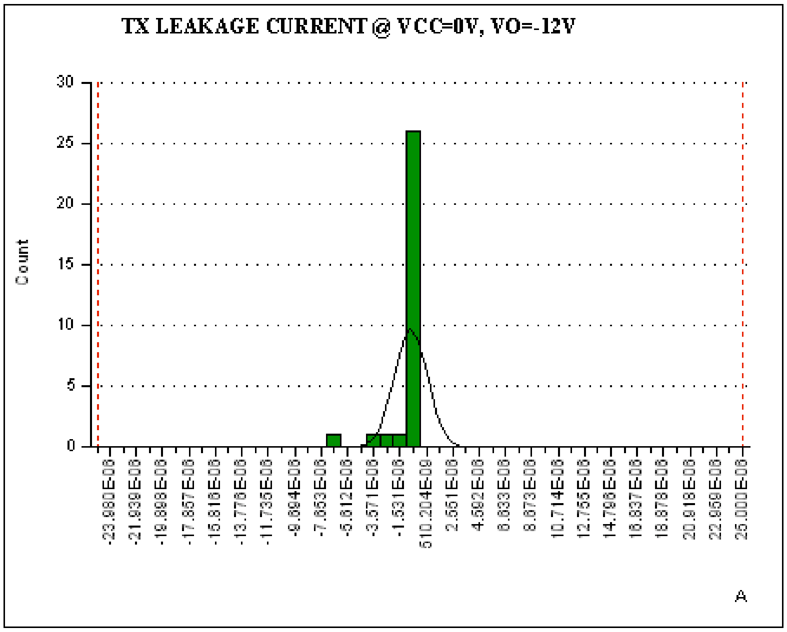
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=22.000, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

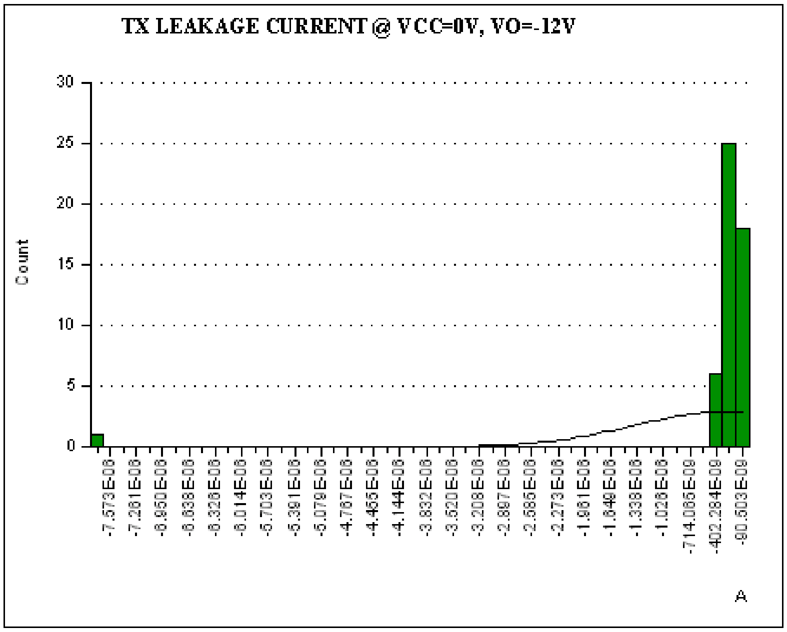
Min	-6.731E-06	**Skew**	-3.8443
Max	-261.931E-09	**StatHigh**	N/A
Mean	-982.253E-09	**StatLow**	N/A
StdDev	1.256E-06	**NWithinSpec**	30
25%	-759.785E-09	**NOutsideSpec**	0
Mean+3*StdDev	2.785E-06	**90%**	-399.284E-09
		Range	6.470E-06
Mean-3*StdDev	-4.750E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.000, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-7.729E-06	**StatLow**	N/A
Max	-90.503E-09	**NWithinSpec**	N/A
Mean	-361.230E-09	**NOutsideSpec**	N/A
StdDev	1.067E-06	**90%**	-109.540E-09
25%	-273.755E-09	**Range**	7.639E-06
Mean+3*StdDev	2.838E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-3.561E-06	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-7.0041		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3: 3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

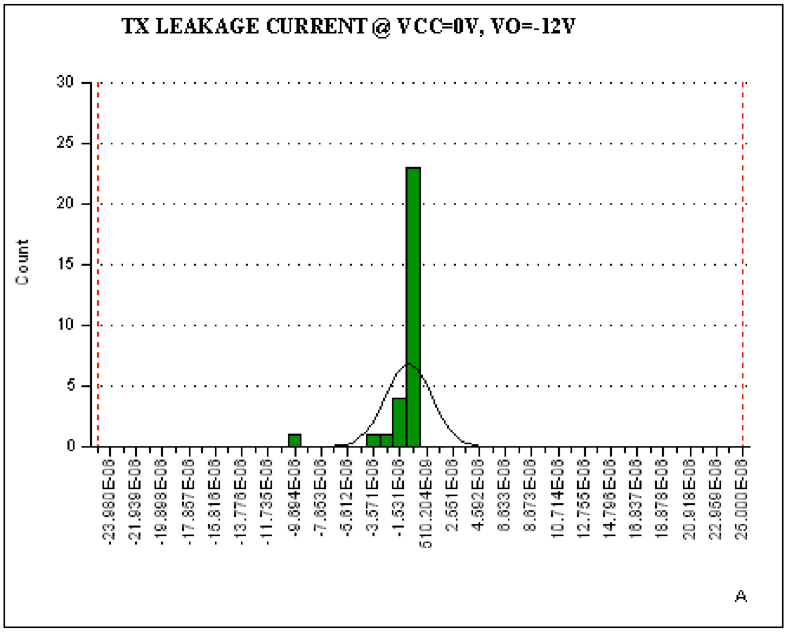
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=22.001, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

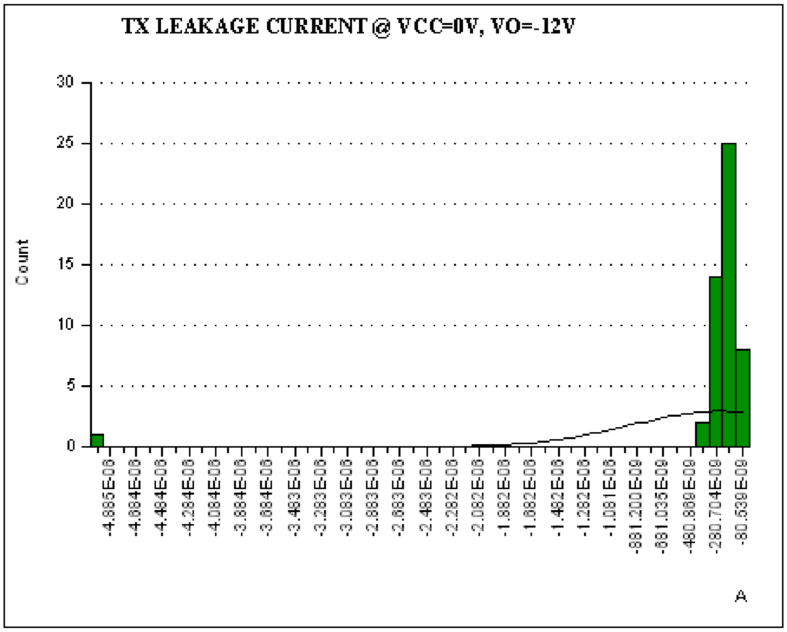
Min	-9.578E-06	**Skew**	-4.0957
Max	-199.218E-09	**StatHigh**	N/A
Mean	-1.146E-06	**StatLow**	N/A
StdDev	1.778E-06	**NWithinSpec**	30
25%	-878.064E-09	**NOutsideSpec**	0
Mean+3*StdDev	4.187E-06	**90%**	-283.953E-09
		Range	9.379E-06
Mean-3*StdDev	-6.479E-06	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.001, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-4.985E-06	**StatLow**	N/A
Max	-80.539E-09	**NWithinSpec**	N/A
Mean	-297.131E-09	**NOutsideSpec**	N/A
StdDev	680.233E-09	**90%**	-117.233E-09
25%	-256.904E-09	**Range**	4.904E-06
Mean+3*StdDev	1.744E-06	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-2.338E-06	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-6.9492		
StatHigh	N/A		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

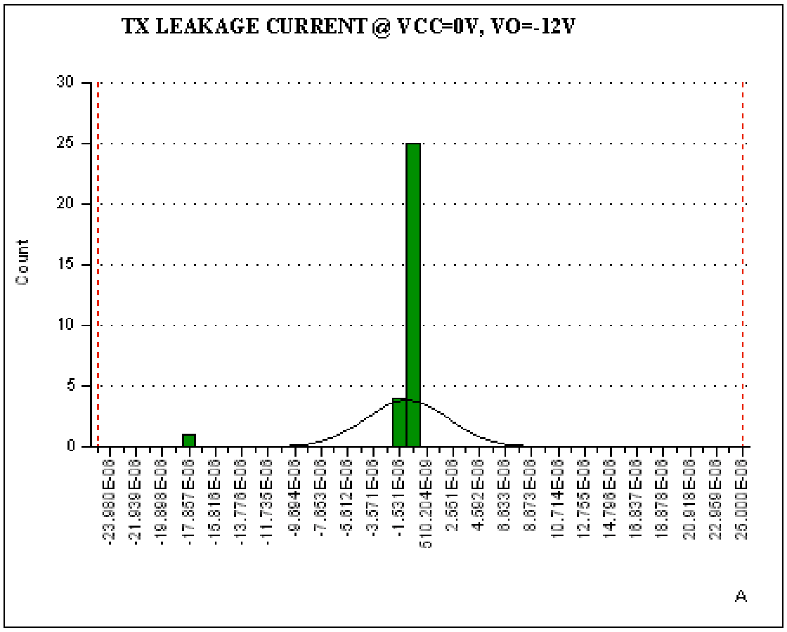
Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=22.002, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

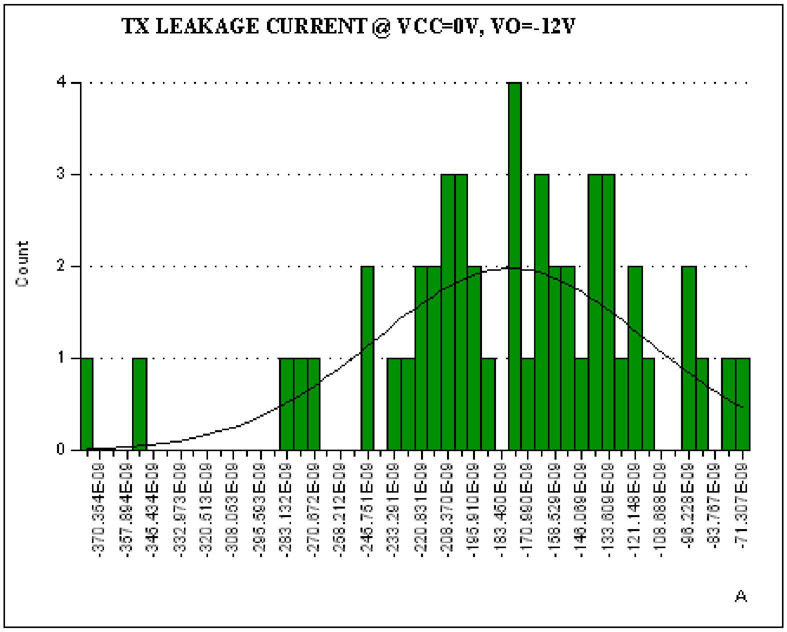
Min	-17.984E-06	**Skew**	-5.3897
Max	-211.596E-09	**StatHigh**	N/A
Mean	-1.236E-06	**StatLow**	N/A
StdDev	3.179E-06	**NWithinSpec**	30
25%	-810.165E-09	**NOutsideSpec**	0
Mean+3*StdDev	8.302E-06	**90%**	-255.529E-09
		Range	17.772E-06
Mean-3*StdDev	-10.774E-06	**NOutsideSpec**	0
Cpk	2.4915		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.002, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=-12V



Statistics: (A)

Min	-376.584E-09	**StatLow**	N/A
Max	-71.307E-09	**NWithinSpec**	N/A
Mean	-181.241E-09	**NOutsideSpec**	N/A
StdDev	62.822E-09	**90%**	-105.697E-09
25%	-213.689E-09	**Range**	305.277E-09
Mean+3*StdDev	7.227E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-369.708E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	-0.8728		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

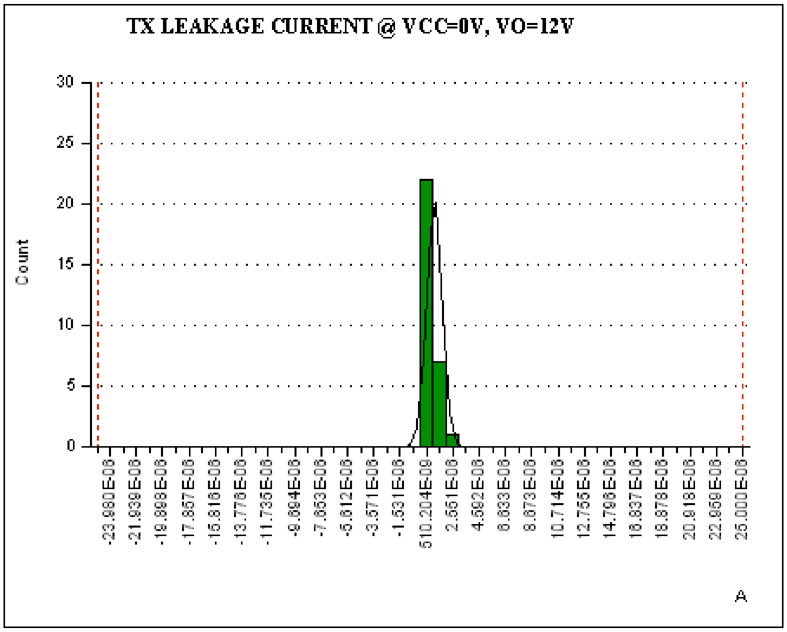
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=22.003, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

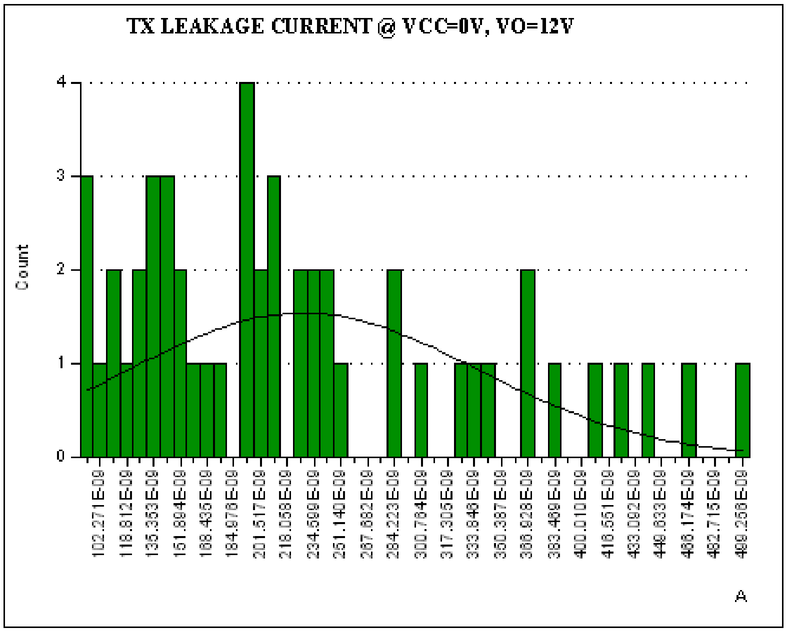
Min	142.061E-09	**Skew**	0.9501
Max	2.146E-06	**StatHigh**	N/A
Mean	834.804E-09	**StatLow**	N/A
StdDev	581.706E-09	**NWithinSpec**	30
25%	424.135E-09	**NOutsideSpec**	0
Mean+3*StdDev	2.580E-06	**90%**	1.856E-06
		Range	2.004E-06
Mean-3*StdDev	-910.314E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.003, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	94.001E-09	**StatLow**	N/A
Max	499.256E-09	**NWithinSpec**	N/A
Mean	226.590E-09	**NOutsideSpec**	N/A
StdDev	107.084E-09	**90%**	395.688E-09
25%	141.679E-09	**Range**	405.256E-09
Mean+3*StdDev	547.842E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-94.662E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.8865		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

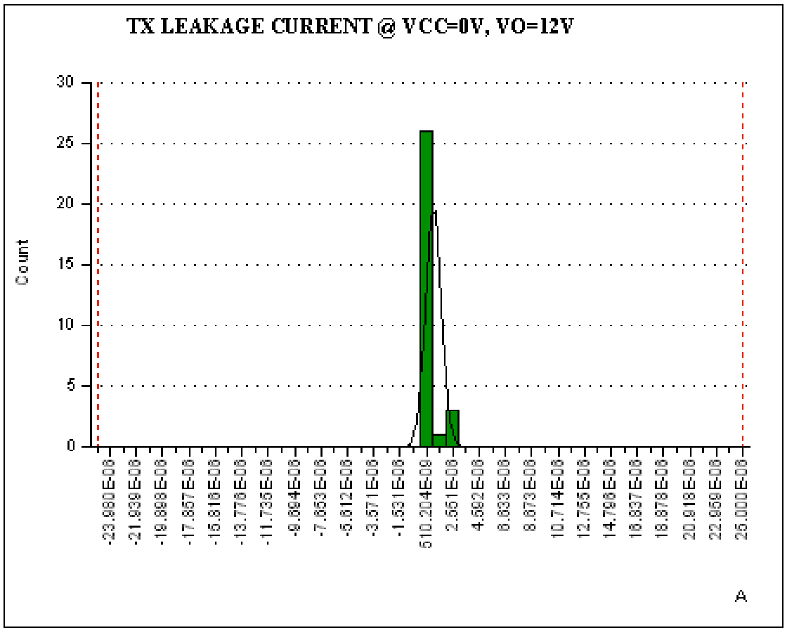
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=22.004, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

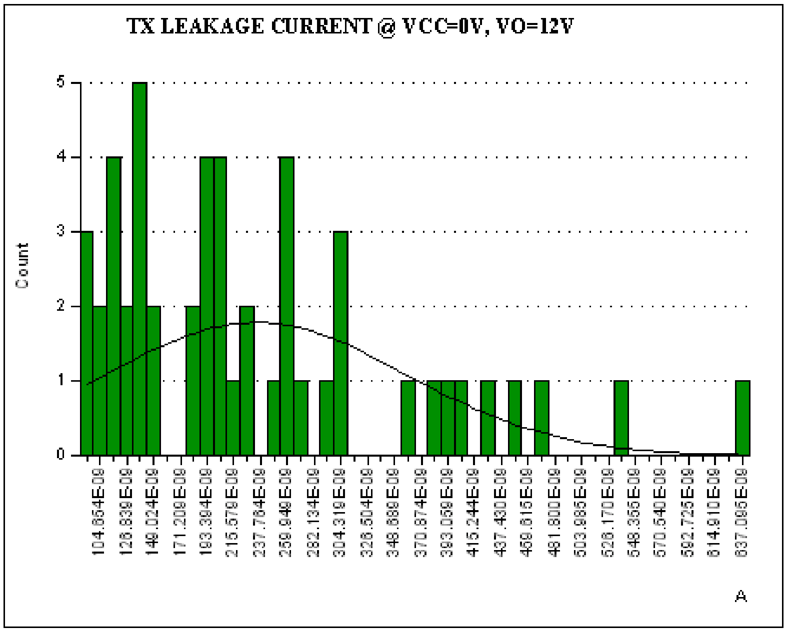
Min	94.776E-09	**Skew**	1.3552
Max	2.230E-06	**StatHigh**	N/A
Mean	761.261E-09	**StatLow**	N/A
StdDev	578.670E-09	**NWithinSpec**	30
25%	356.367E-09	**NOutsideSpec**	0
Mean+3*StdDev	2.497E-06	**90%**	1.856E-06
		Range	2.135E-06
Mean-3*StdDev	-974.749E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.004, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	93.561E-09	**StatLow**	N/A
Max	637.095E-09	**NWithinSpec**	N/A
Mean	232.720E-09	**NOutsideSpec**	N/A
StdDev	124.076E-09	**90%**	412.240E-09
25%	134.578E-09	**Range**	543.534E-09
Mean+3*StdDev	604.948E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-139.507E-09	**Cpl**	N/A
Cpk	N/A	**Cpu**	N/A
Skew	1.2599		
StatHigh	N/A		

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

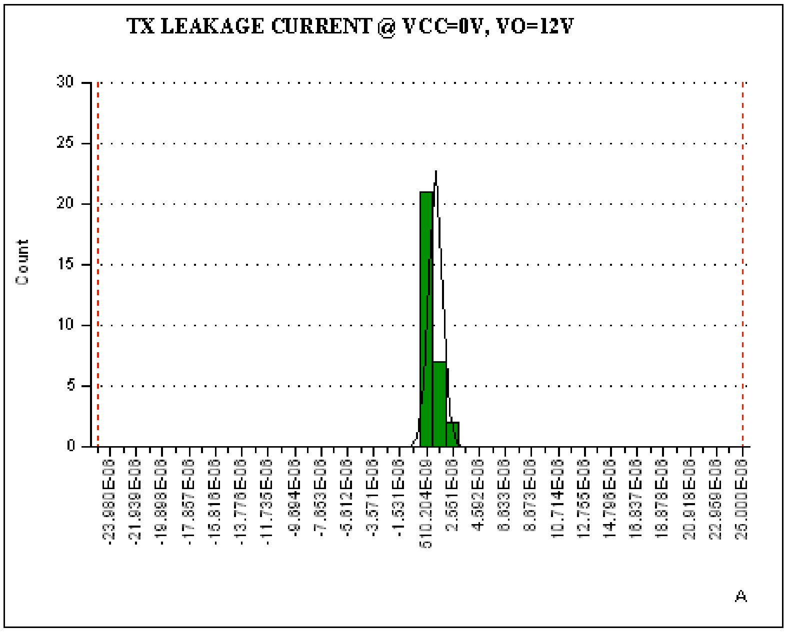
Conditions

Vcc	temp
3V	25C

Data: Raw Data

Thu 30 Mar 2006, 01:12 PM

Test.Number=22.005, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

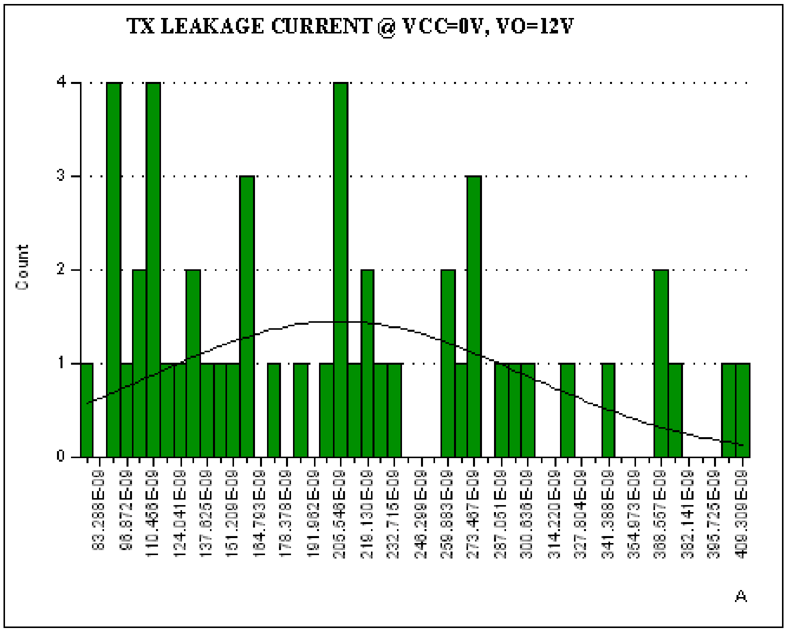
Min	183.747E-09	**Skew**	0.8680
Max	2.335E-06	**StatHigh**	N/A
Mean	915.783E-09	**StatLow**	N/A
StdDev	530.600E-09	**NWithinSpec**	30
25%	585.262E-09	**NOutsideSpec**	0
Mean+3*StdDev	2.508E-06	**90%**	1.741E-06
		Range	2.152E-06
Mean-3*StdDev	-676.017E-09	**NOutsideSpec**	0
Cpk	>4.0000		

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
C30P44: 3	MS1105GZ	SP3243EB	_	3VRoomchar	Episil	2umcmos	20-MAR-2006	N/A	SP3243ECH.AT	-	0

Data: Raw Data

Test.Number=22.005, Test.Name=TX LEAKAGE CURRENT @ VCC=0V, VO=12V



Statistics: (A)

Min	76.496E-09	**StatLow**	N/A
Max	409.309E-09	**NWithinSpec**	N/A
Mean	203.249E-09	**NOutsideSpec**	N/A
StdDev	93.242E-09	**90%**	353.572E-09
25%	120.590E-09	**Range**	332.814E-09
Mean+3*StdDev	482.975E-09	**NOutsideSpec**	N/A
		Cp	N/A
Mean-3*StdDev	-76.477E-09	**Cpl**	N/A
		Cpu	N/A
Cpk	N/A		
Skew	0.5820		
StatHigh	N/A		

Attributes

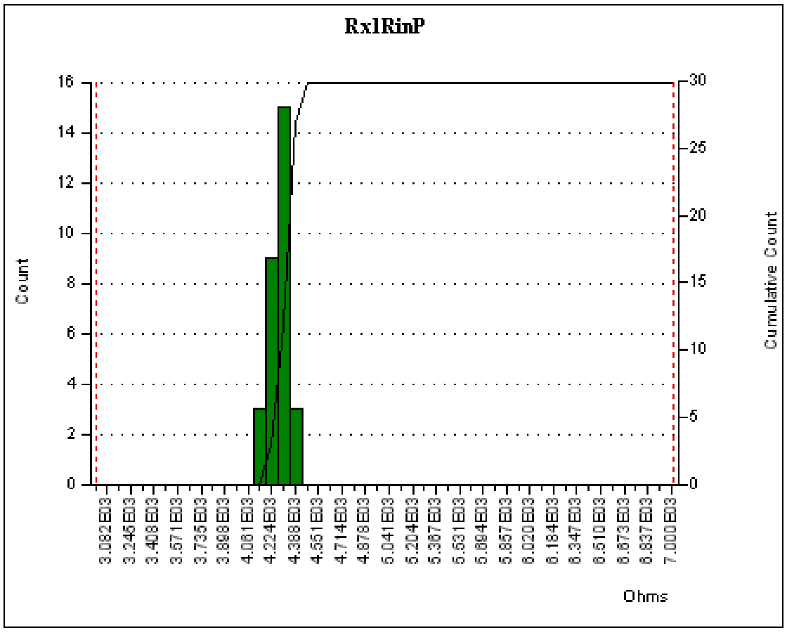
Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
96890cr3:3	MS1324AZ	SP3243EB	_	Char	Hillview	N/A	27-JUN-2003	N/A	SP3243ECH.AT	-	0

Conditions

Vcc	**temp**
3V	25C

Data: Raw Data

Test.Number=28.0, Test.Name=Rx1RinP



Statistics: (Ohms)

Max	4.413E03	**25%**	4.230E03	**SpecHigh**	7.000E03
Mean	4.275E03	**10%**	4.184E03	**SpecLow**	3.000E03
Min	4.140E03	**N**	30	**PctWithinSpec**	100.00
Range	273.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	65.261	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9579	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2739	**Cpk**	>4.0000		
90%	4.346E03	**Skew**	-0.3269		
75%	4.314E03	**Kurtosis**	-0.1170		
Median	4.298E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

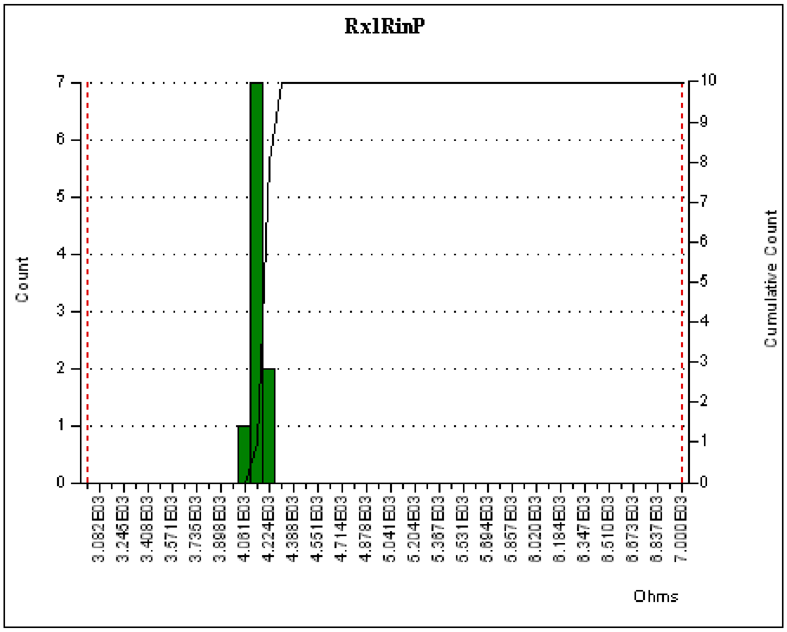
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=28.0, Test.Name=Rx1RinP



Statistics: (Ohms)

Max	4.199E03	**25%**	4.115E03	**SpecHigh**	7.000E03
Mean	4.143E03	**10%**	4.093E03	**SpecLow**	3.000E03
Min	4.072E03	**N**	10	**PctWithinSpec**	100.00
Range	127.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	38.871	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9627	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.8164	**Cpk**	>4.0000		
90%	4.196E03	**Skew**	-0.1612		
75%	4.172E03	**Kurtosis**	-0.2253		
Median	4.135E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

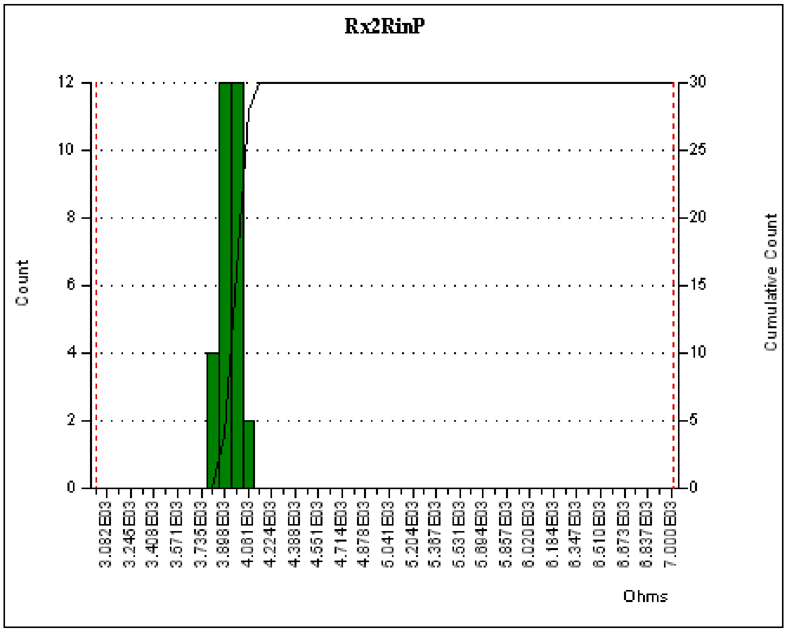
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=29.0, Test.Name=Rx2RinP



Statistics: (Ohms)

Max	4.059E03	**25%**	3.883E03	**SpecHigh**	7.000E03
Mean	3.925E03	**10%**	3.833E03	**SpecLow**	3.000E03
Min	3.791E03	**N**	30	**PctWithinSpec**	100.00
Range	268.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	62.785	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9699	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.5358	**Cpk**	>4.0000		
90%	3.990E03	**Skew**	-0.3021		
75%	3.965E03	**Kurtosis**	-0.0479		
Median	3.936E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

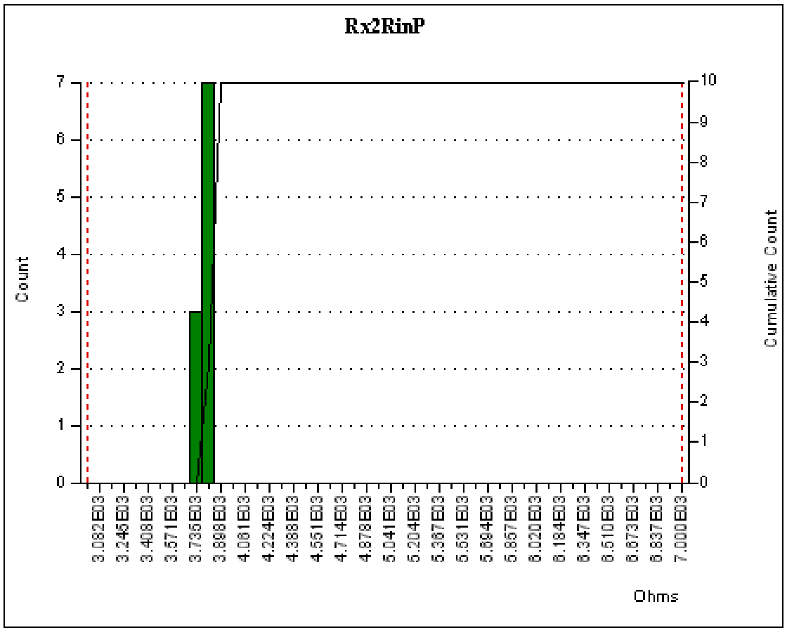
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=29.0, Test.Name=Rx2RinP



Statistics: (Ohms)

Max	3.855E03	**25%**	3.762E03	**SpecHigh**	7.000E03
Mean	3.793E03	**10%**	3.736E03	**SpecLow**	3.000E03
Min	3.711E03	**N**	10	**PctWithinSpec**	100.00
Range	144.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	43.579	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9591	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.7761	**Cpk**	>4.0000		
90%	3.853E03	**Skew**	-0.2882		
75%	3.816E03	**Kurtosis**	0.1763		
Median	3.792E03				

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

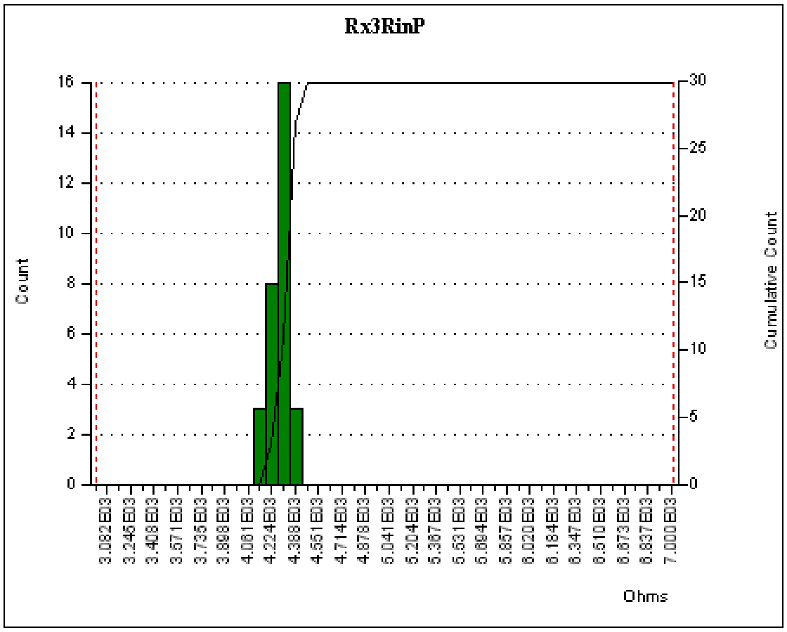
Stat limits applied

StatHigh	**StatLow**	**PctWithinStat**	**PctDefStat**	**NWithinStat**	**NOutsideStat**
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=30.0, Test.Name=Rx3RinP



Statistics: (Ohms)

Max	4.408E03	**25%**	4.233E03	**SpecHigh**	7.000E03
Mean	4.276E03	**10%**	4.184E03	**SpecLow**	3.000E03
Min	4.148E03	**N**	30	**PctWithinSpec**	100.00
Range	260.000	**Cp**	>4.0000		
StdDev	63.406	**Cpl**	>4.0000	**PctDefSpec**	0
W	0.9694	**Cpu**	>4.0000	**NWithinSpec**	30
WpValue	0.5241	**Cpk**	>4.0000	**NOutsideSpec**	0
90%	4.344E03	**Skew**	-0.3066		
75%	4.314E03	**Kurtosis**	-0.1307		
Median	4.293E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

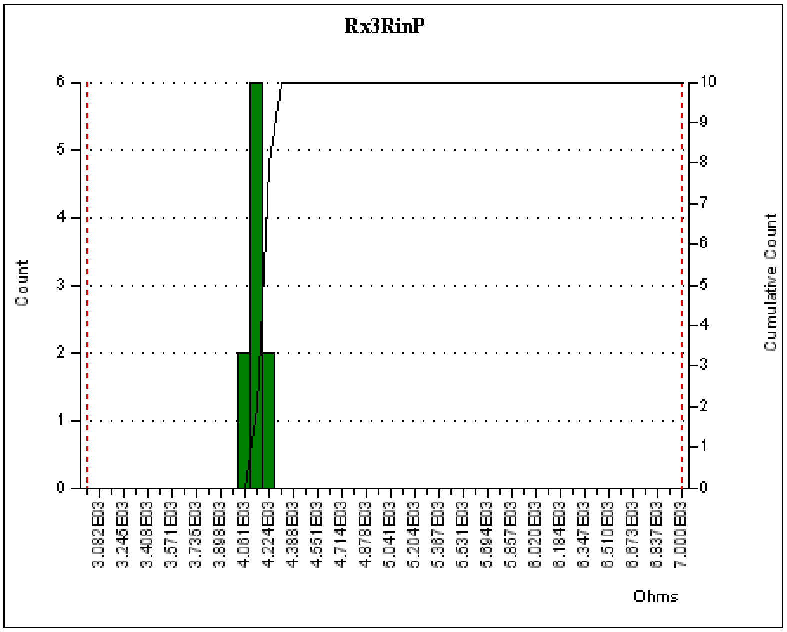
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=30.0, Test.Name=Rx3RinP



Statistics: (Ohms)

Max	4.208E03	**25%**	4.119E03	**SpecHigh**	7.000E03
Mean	4.145E03	**10%**	4.088E03	**SpecLow**	3.000E03
Min	4.074E03	**N**	10	**PctWithinSpec**	100.00
Range	134.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	42.321	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9663	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.8541	**Cpk**	>4.0000		
90%	4.207E03	**Skew**	0.0659		
75%	4.171E03	**Kurtosis**	-0.3581		
Median	4.142E03				

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

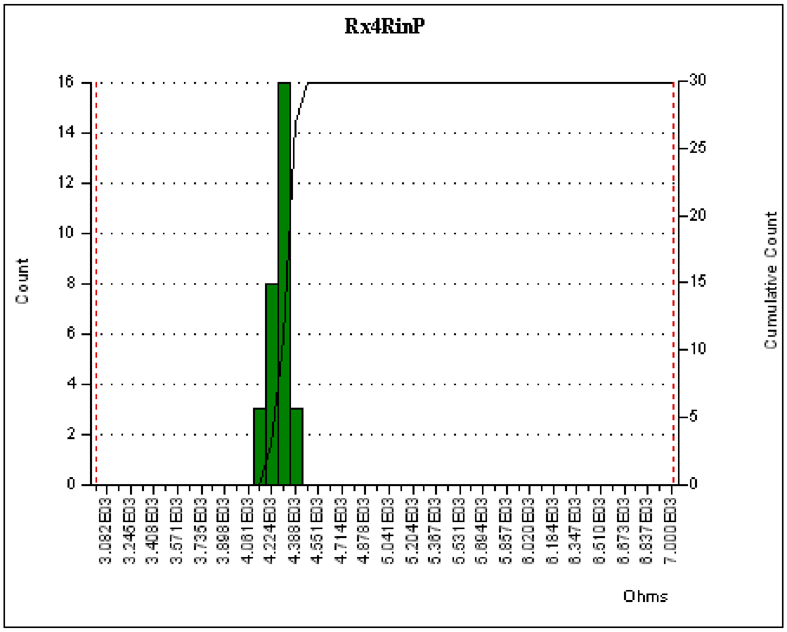
Stat limits applied

StatHigh	**StatLow**	**PctWithinStat**	**PctDefStat**	**NWithinStat**	**NOutsideStat**
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=31.0, Test.Name=Rx4RinP



Statistics: (Ohms)

Max	4.419E03	**25%**	4.229E03	**SpecHigh**	7.000E03
Mean	4.278E03	**10%**	4.187E03	**SpecLow**	3.000E03
Min	4.137E03	**N**	30	**PctWithinSpec**	100.00
Range	282.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	64.908	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9701	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.5425	**Cpk**	>4.0000		
90%	4.346E03	**Skew**	-0.2806		
75%	4.319E03	**Kurtosis**	0.0669		
Median	4.298E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

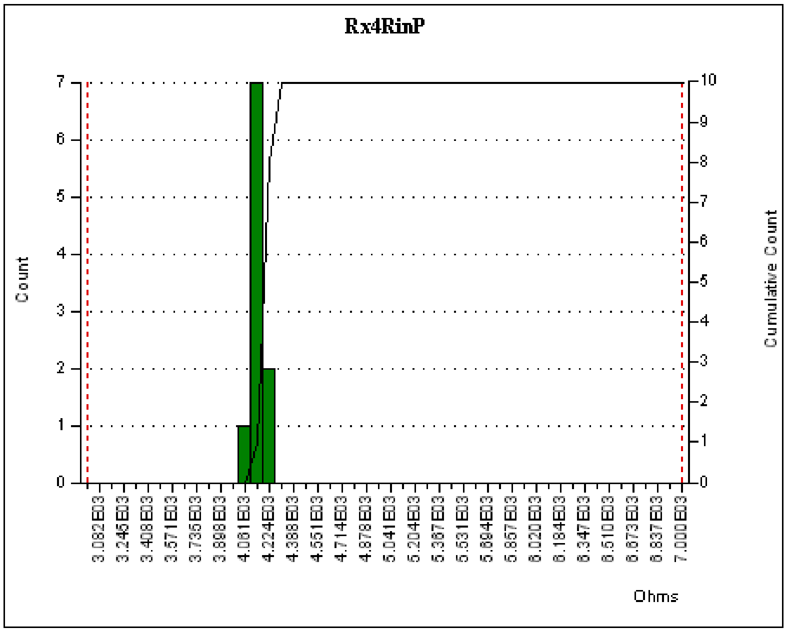
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=31.0, Test.Name=Rx4RinP



Statistics: (Ohms)

Max	4.197E03	**25%**	4.122E03	**SpecHigh**	7.000E03
Mean	4.145E03	**10%**	4.093E03	**SpecLow**	3.000E03
Min	4.075E03	**N**	10	**PctWithinSpec**	100.00
Range	122.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	38.159	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9573	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.7546	**Cpk**	>4.0000		
90%	4.197E03	**Skew**	-0.2174		
75%	4.174E03	**Kurtosis**	-0.1905		
Median	4.138E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

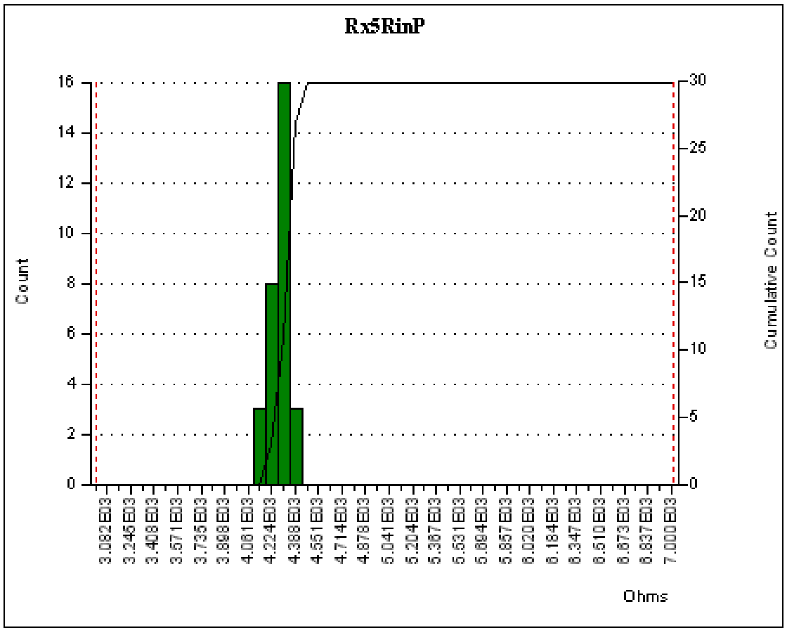
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=32.0, Test.Name=Rx5RinP



Statistics: (Ohms)

Max	4.408E03	**25%**	4.228E03	**SpecHigh**	7.000E03
Mean	4.272E03	**10%**	4.183E03	**SpecLow**	3.000E03
Min	4.140E03	**N**	30	**PctWithinSpec**	100.00
Range	268.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	62.771	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9690	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.5122	**Cpk**	>4.0000		
90%	4.341E03	**Skew**	-0.3235		
75%	4.312E03	**Kurtosis**	0.1675		
Median	4.288E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

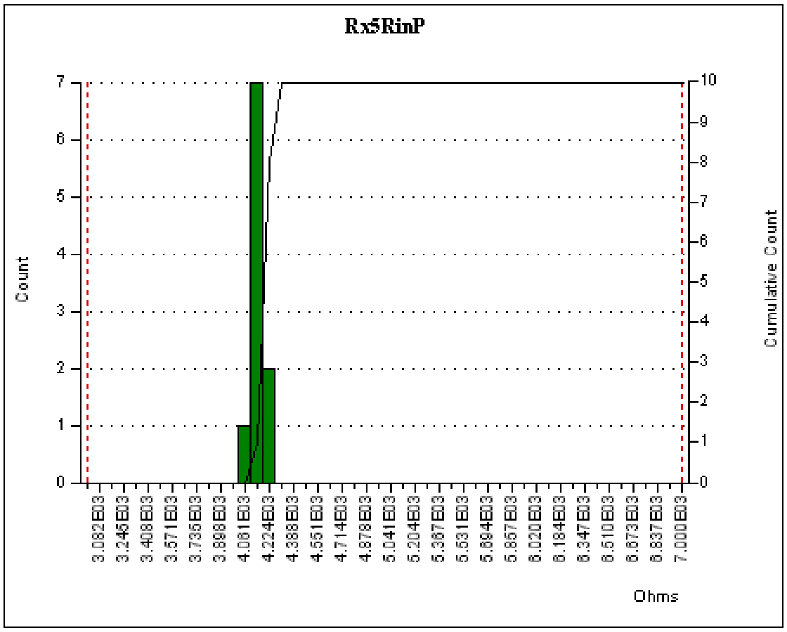
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=32.0, Test.Name=Rx5RinP



Statistics: (Ohms)

Max	4.205E03	**25%**	4.118E03	**SpecHigh**	7.000E03
Mean	4.142E03	**10%**	4.095E03	**SpecLow**	3.000E03
Min	4.071E03	**N**	10	**PctWithinSpec**	100.00
Range	134.000	**Cp**	>4.0000		
StdDev	39.216	**Cpl**	>4.0000	**PctDefSpec**	0
W	0.9543	**Cpu**	>4.0000	**NWithinSpec**	10
WpValue	0.7193	**Cpk**	>4.0000	**NOutsideSpec**	0
90%	4.200E03	**Skew**	0.0445		
75%	4.159E03	**Kurtosis**	0.3220		
Median	4.138E03				

Attributes

Lot: Wafers	**Maskset ID**	**Device**	**Device Rev**	**Operation**	**Foundry**	**Process**	**Date Tested**	**Tester**	**Test Program**	**Sequence**	**Retest**
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

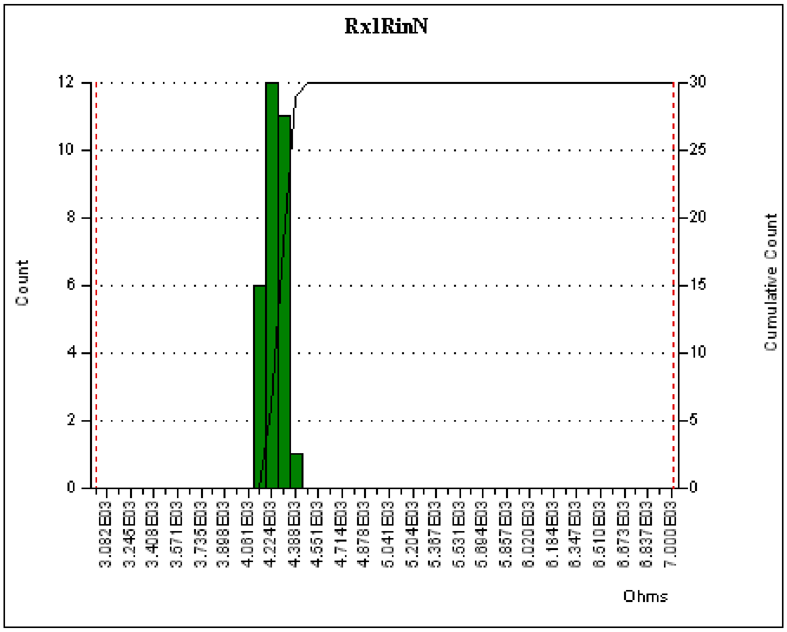
Stat limits applied

StatHigh	**StatLow**	**PctWithinStat**	**PctDefStat**	**NWithinStat**	**NOutsideStat**
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=33.0, Test.Name=Rx1RinN



Statistics: (Ohms)

Max	4.373E03	**25%**	4.197E03	**SpecHigh**	7.000E03
Mean	4.240E03	**10%**	4.147E03	**SpecLow**	3.000E03
Min	4.105E03	**N**	30	**PctWithinSpec**	100.00
Range	268.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	64.651	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9562	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.2467	**Cpk**	>4.0000		
90%	4.309E03	**Skew**	-0.3640		
75%	4.279E03	**Kurtosis**	-0.0769		
Median	4.261E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

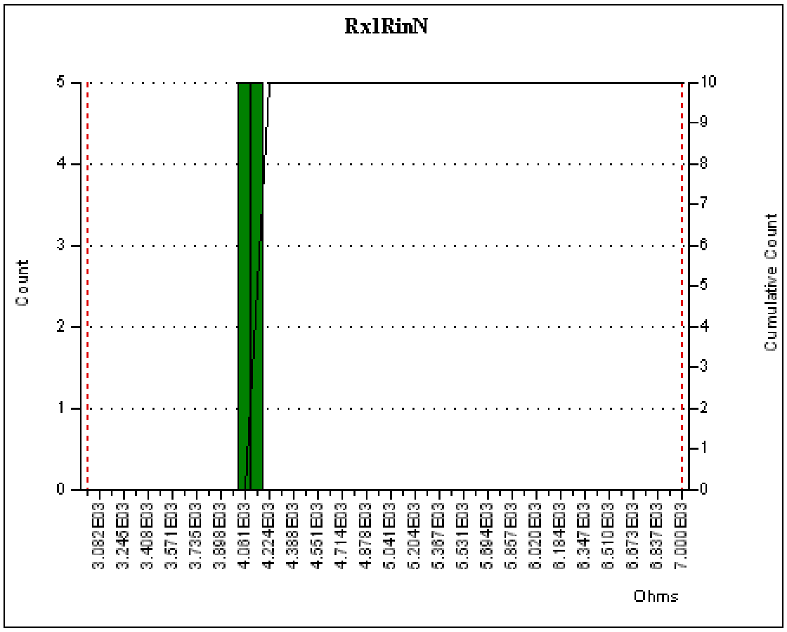
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=33.0, Test.Name=Rx1RinN



Statistics: (Ohms)

Max	4.162E03	**25%**	4.082E03	**SpecHigh**	7.000E03
Mean	4.107E03	**10%**	4.061E03	**SpecLow**	3.000E03
Min	4.039E03	**N**	10	**PctWithinSpec**	100.00
Range	123.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	36.855	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9696	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.8872	**Cpk**	>4.0000		
90%	4.157E03	**Skew**	-0.2232		
75%	4.134E03	**Kurtosis**	-0.0558		
Median	4.103E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

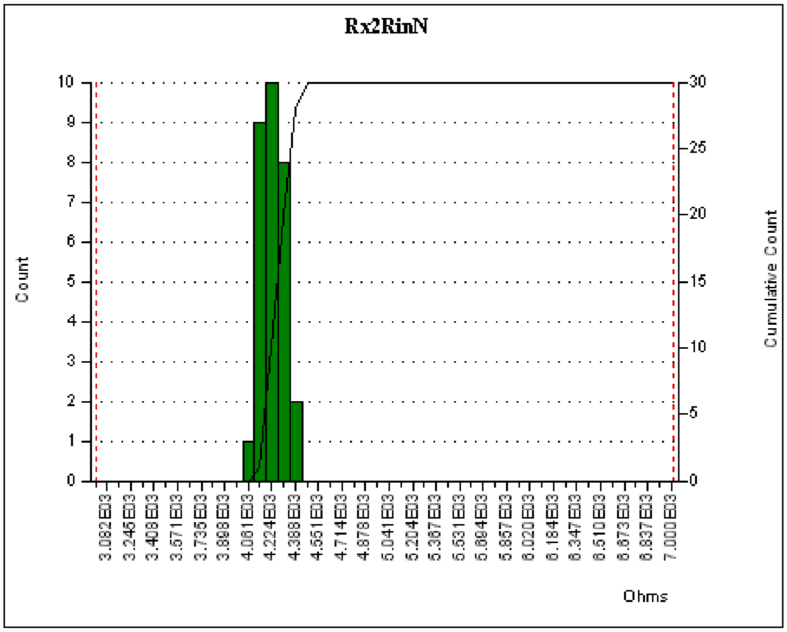
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=34.0, Test.Name=Rx2RinN



Statistics: (Ohms)

Max	4.403E03	**25%**	4.165E03	**SpecHigh**	7.000E03
Mean	4.222E03	**10%**	4.109E03	**SpecLow**	3.000E03
Min	4.094E03	**N**	30	**PctWithinSpec**	100.00
Range	309.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	80.499	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9705	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.5528	**Cpk**	>4.0000		
90%	4.319E03	**Skew**	0.2114		
75%	4.291E03	**Kurtosis**	-0.5515		
Median	4.223E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

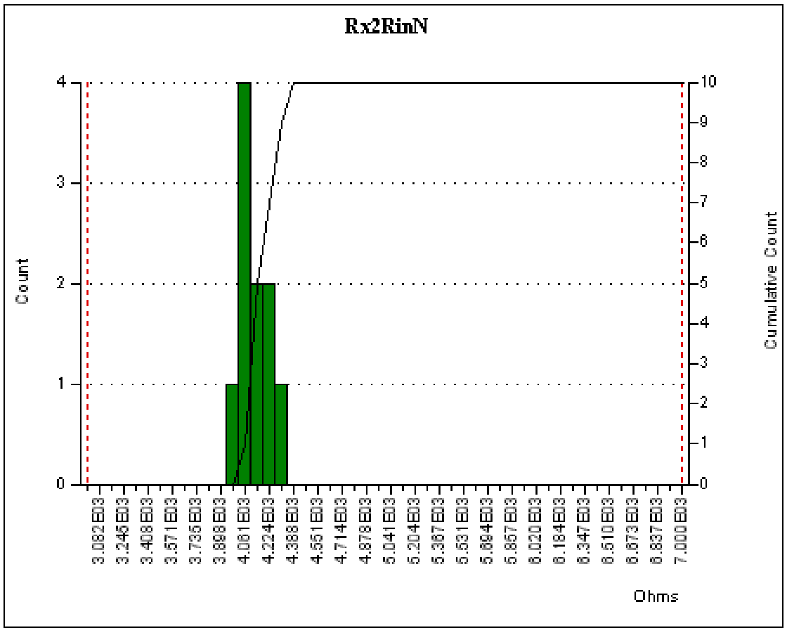
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=34.0, Test.Name=Rx2RinN



Statistics: (Ohms)

Max	4.272E03	**25%**	4.044E03	**SpecHigh**	7.000E03
Mean	4.113E03	**10%**	4.013E03	**SpecLow**	3.000E03
Min	3.995E03	**N**	10	**PctWithinSpec**	100.00
Range	277.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	88.377	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9559	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.7379	**Cpk**	>4.0000		
90%	4.238E03	**Skew**	0.5123		
75%	4.190E03	**Kurtosis**	-0.7068		
Median	4.090E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

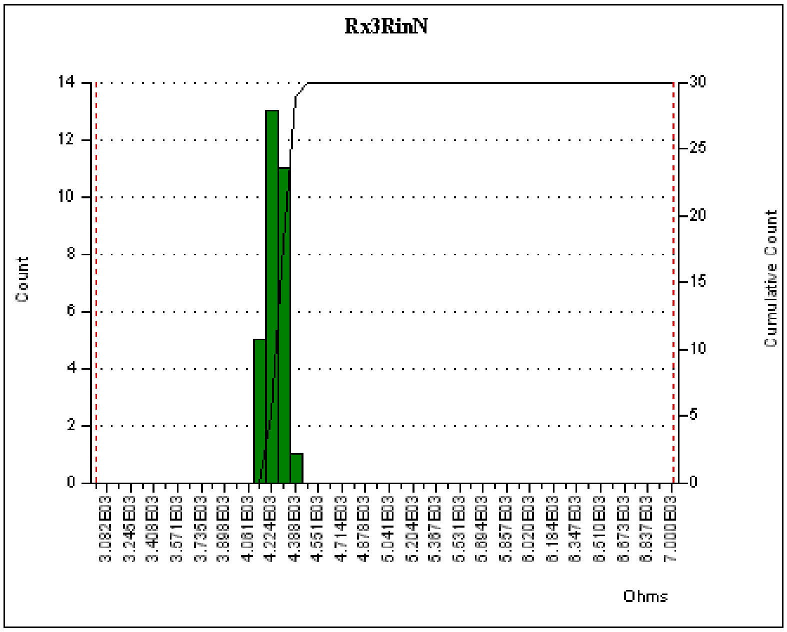
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=35.0, Test.Name=Rx3RinN



Statistics: (Ohms)

Max	4.373E03	**25%**	4.198E03	**SpecHigh**	7.000E03
Mean	4.241E03	**10%**	4.151E03	**SpecLow**	3.000E03
Min	4.112E03	**N**	30	**PctWithinSpec**	100.00
Range	261.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	62.946	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9699	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.5374	**Cpk**	>4.0000		
90%	4.309E03	**Skew**	-0.3201		
75%	4.280E03	**Kurtosis**	-0.0834		
Median	4.258E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

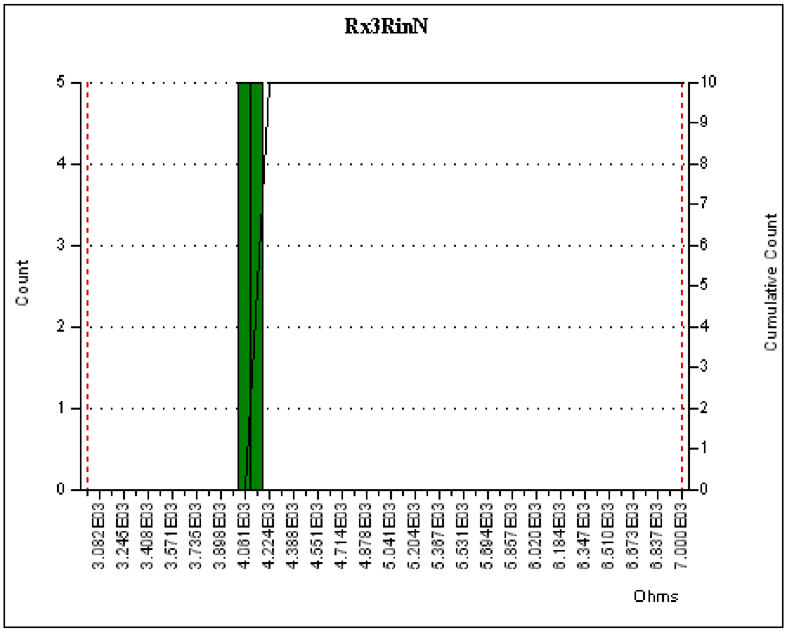
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=35.0, Test.Name=Rx3RinN



Statistics: (Ohms)

Max	4.173E03	**25%**	4.086E03	**SpecHigh**	7.000E03
Mean	4.110E03	**10%**	4.053E03	**SpecLow**	3.000E03
Min	4.040E03	**N**	10	**PctWithinSpec**	100.00
Range	133.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	41.775	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9668	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.8600	**Cpk**	>4.0000		
90%	4.171E03	**Skew**	0.0666		
75%	4.136E03	**Kurtosis**	-0.3180		
Median	4.106E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

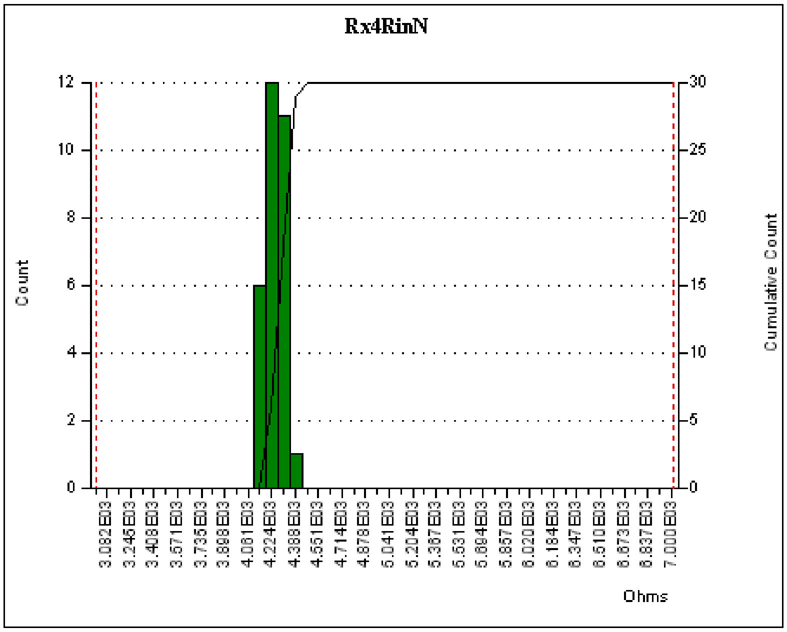
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=36.0, Test.Name=Rx4RinN



Statistics: (Ohms)

Max	4.382E03	**25%**	4.196E03	**SpecHigh**	7.000E03
Mean	4.242E03	**10%**	4.151E03	**SpecLow**	3.000E03
Min	4.103E03	**N**	30	**PctWithinSpec**	100.00
Range	279.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	64.538	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9686	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.5020	**Cpk**	>4.0000		
90%	4.311E03	**Skew**	-0.2841		
75%	4.282E03	**Kurtosis**	0.0631		
Median	4.261E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

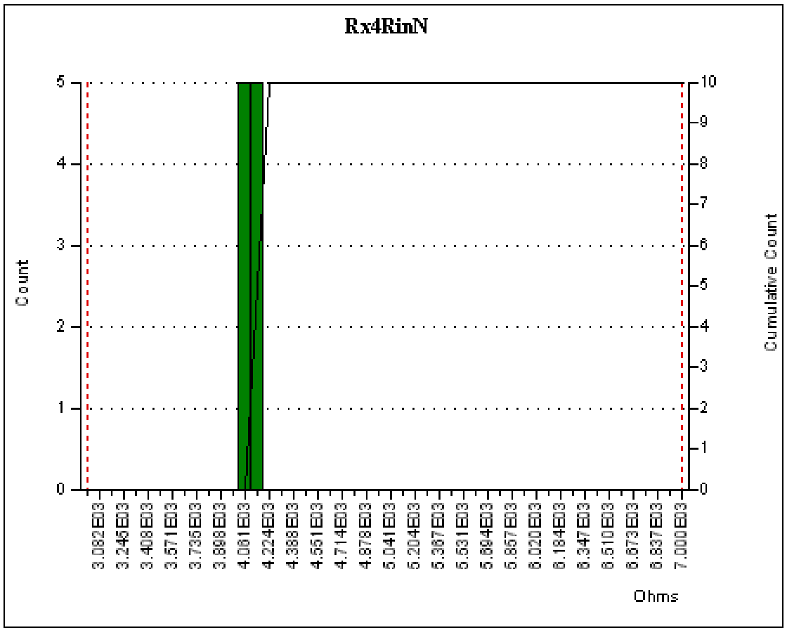
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=36.0, Test.Name=Rx4RinN



Statistics: (Ohms)

Max	4.162E03	**25%**	4.089E03	**SpecHigh**	7.000E03
Mean	4.110E03	**10%**	4.059E03	**SpecLow**	3.000E03
Min	4.041E03	**N**	10	**PctWithinSpec**	100.00
Range	121.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	37.882	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9560	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.7393	**Cpk**	>4.0000		
90%	4.162E03	**Skew**	-0.1836		
75%	4.138E03	**Kurtosis**	-0.2156		
Median	4.103E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

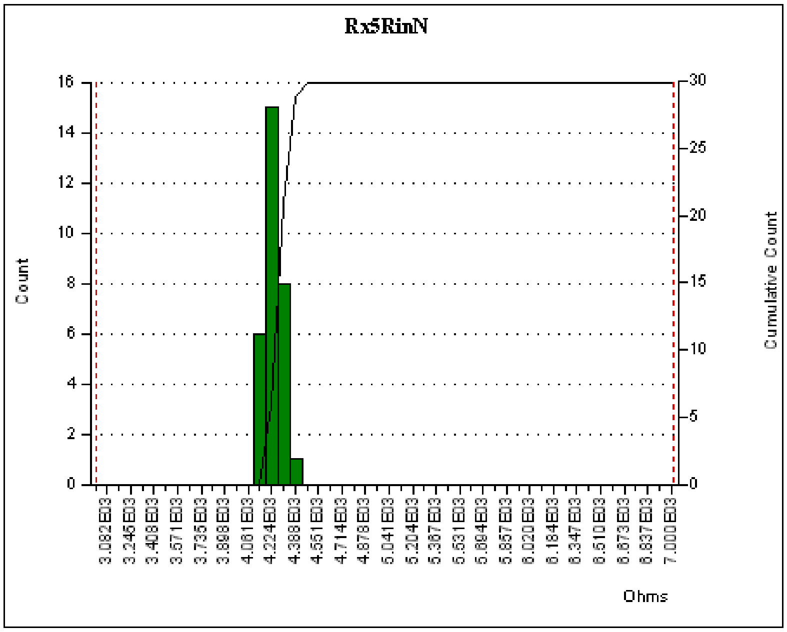
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=37.0, Test.Name=Rx5RinN



Statistics: (Ohms)

Max	4.372E03	**25%**	4.195E03	**SpecHigh**	7.000E03
Mean	4.236E03	**10%**	4.148E03	**SpecLow**	3.000E03
Min	4.103E03	**N**	30	**PctWithinSpec**	100.00
Range	269.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	62.459	**Cpl**	>4.0000	**NWithinSpec**	30
W	0.9670	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.4600	**Cpk**	>4.0000		
90%	4.304E03	**Skew**	-0.3526		
75%	4.277E03	**Kurtosis**	0.2551		
Median	4.253E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
C30P46: 1	MS1105GZ	SP3243EB	_	Roomchar	Episil	2umcmos	28-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Data: Raw Data

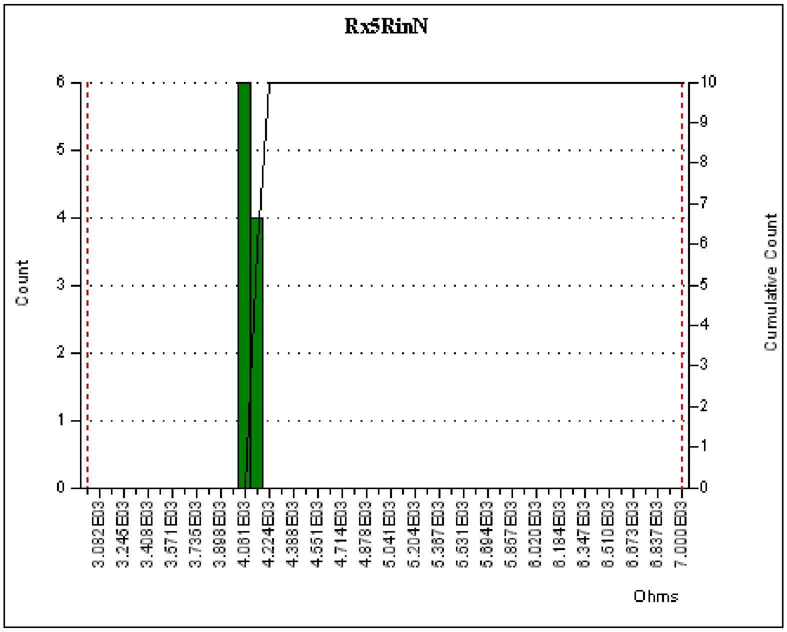
Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0

Test.Number=37.0, Test.Name=Rx5RinN



Statistics: (Ohms)

Max	4.167E03	**25%**	4.084E03	**SpecHigh**	7.000E03
Mean	4.106E03	**10%**	4.059E03	**SpecLow**	3.000E03
Min	4.037E03	**N**	10	**PctWithinSpec**	100.00
Range	130.000	**Cp**	>4.0000	**PctDefSpec**	0
StdDev	38.206	**Cpl**	>4.0000	**NWithinSpec**	10
W	0.9489	**Cpu**	>4.0000	**NOutsideSpec**	0
WpValue	0.6554	**Cpk**	>4.0000		
90%	4.163E03	**Skew**	0.0633		
75%	4.121E03	**Kurtosis**	0.3406		
Median	4.101E03				

Attributes

Lot: Wafers	Maskset ID	Device	Device Rev	Operation	Foundry	Process	Date Tested	Tester	Test Program	Sequence	Retest
SP3243EBEA_0336_R: N/A	MS1324	sp3243EB	_	hotchar	N/A	N/A	27-MAR-2006	ETS564	I3243dual13_e_qa.02/21/2006	-	0

Conditions

Temp
25C

Data: Raw Data

Stat limits applied

StatHigh	StatLow	PctWithinStat	PctDefStat	NWithinStat	NOutsideStat
N/A	N/A	N/A	N/A	N/A	N/A

Plot limits applied

NOutsidePlot
0